Radiation Report

TPS7H5021-SEP and TPS7H5021-SP QMLP Neutron Displacement Damage (NDD) Characterization

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the TPS7H5021-SEP and TPS7H5021-SP QMLP device. The results show that all devices were fully functional and within production test limits after having been irradiated up to 1×10^{13} n/cm^2(1MeV(Si) equivalent). A sample size of twelve units were exposed per MIL-STD-883, Method 1017 for neutron irradiation, and an additional three devices were used as control units and were not irradiated. Electrical testing was performed at Texas Instruments before and after neutron irradiation using the production test program for TPS7H5021-SEP and TPS7H5021-SP QMLP.

Table of Contents

1 Overview 2
2 Test Procedures 3
3 Facility 4
4 Results 5
4.1 Data Sheet Electrical Parameters and Associated Tests 5
A Appendix: NDD Report Data 10

List of Figures

Figure 2-1. TPS7H5021-SP QMLP Device 3

List of Tables

Table 1-1. Overview Information 2
Table 2-1. Neutron Irradiation Conditions 3
Table 4-1. Data Sheet Electrical Parameters 5

Trademarks

All trademarks are the property of their respective owners.

Copyright © 2026 Texas Instruments Incorporated

1 Overview

The TPS7H5021-SEP and TPS7H5021-SP QMLP is a radiation-hardness-assured, current mode, single-ended PWM controller with an integrated gate driver that can be utilized in both silicon and gallium nitride (GaN) power semiconductor based converter designs. The TPS7H5020 integrates several key functions, such as soft-start, enable, and adjustable slope compensation while maintaining a small package size. The controller also features a 0.6V ± 1% voltage reference tolerance to support highly accurate power converter designs. The TPS7H5021-SEP is packaged in a plastic 24-pin HTSSOP PWP package.

Table 1-1. Overview Information

TI Device	**TPS7H5021-SEP TPS7H5021-SP QMLP**
TI Part Number	TPS7H5021MPWPTSEP 5962R2420102PYE
VID Number	V62/25651
SMD Number	5962-24201
Device Function	PWM controller with an integrated gate driver
Technology	Linear BiCMOS 7 (LBC7)
Assembly Lot Number / Lot Trace Code	5306470 / 55AT7ZK
Unbiased Quantity Tested	12
Exposure Facility	VPT Rad
Neutron Fluence (1-MeV equivalent)	1.0×10^{12}, 5.0×10^{12}, 1.0×10^{13} n/cm^2
Irradiation Temperature	Room temperature
TI may provide technical, applications or design advice, quality characterization, and reliability data or service providing these items shall not expand or otherwise affect TI's warranties as set forth in the Texas Instruments Incorporated Standard Terms and Conditions of Sale for Semiconductor Products and no obligation or liability shall arise from Semiconductor Products and no obligation or liability shall arise from TI's provision of such items.	

Copyright © 2026 Texas Instruments Incorporated

2 Test Procedures

The TPS7H5021-SEP and TPS7H5021-SP QMLP was electrically pre- and post-tested using the production automated test equipment program.

General test procedures adhered to MIL-STD-883, Method 1017 for Neutron Irradiation of TPS7H5021-SEP and TPS7H5021-SP QMLP. Neutron irradiation conditions are listed in Table 2-1.

Table 2-1. Neutron Irradiation Conditions

Group	Sample Quantity	Neutron Fluence (n/cm^2)	BIAS
A	4	1×10^{12}	Unbiased
B	4	5×10^{12}	Unbiased
C	4	1×10^{13}	Unbiased
Correlation	4	0	N/A

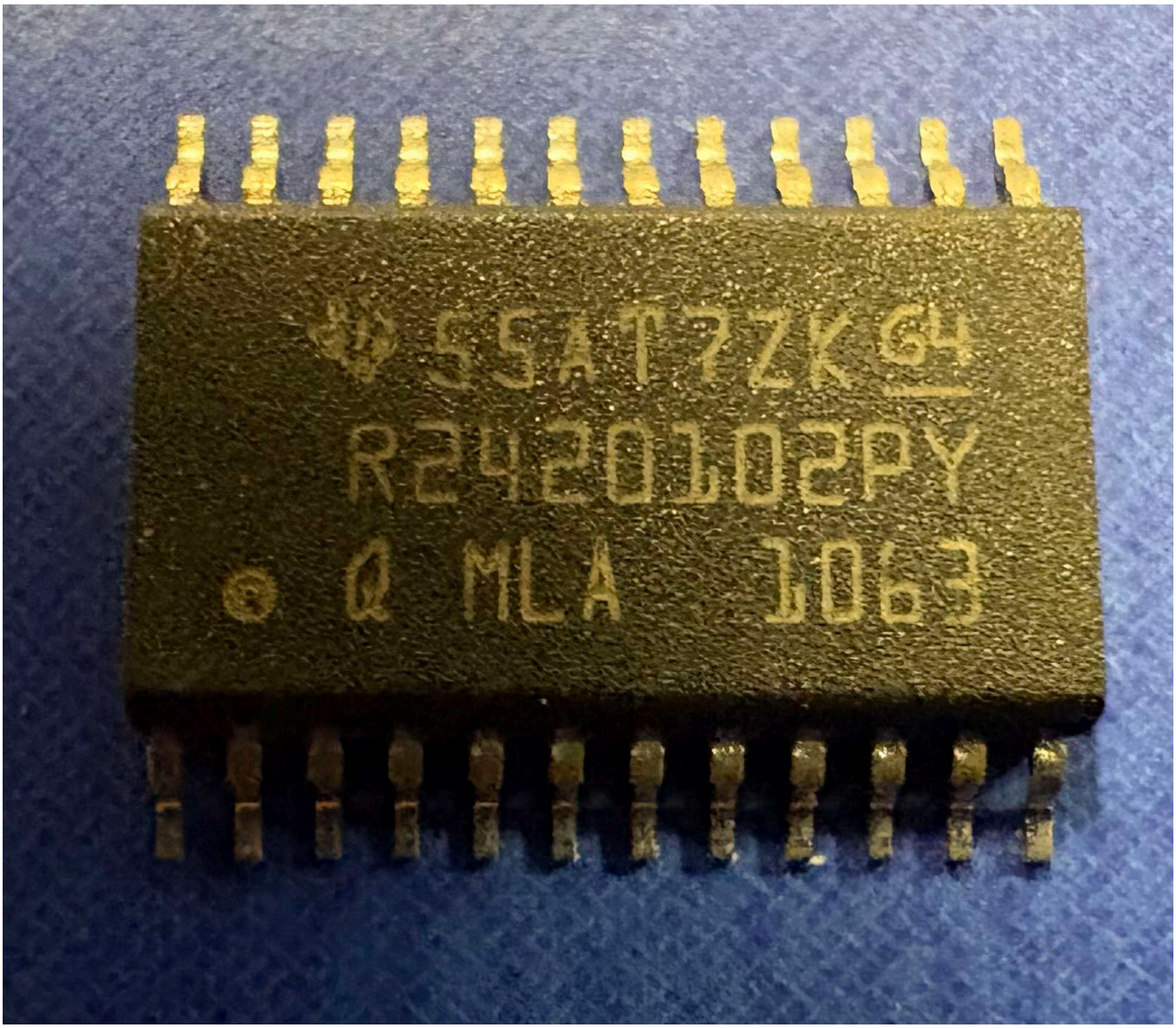


Figure 2-1. TPS7H5021-SP QMLP Device

Copyright © 2026 Texas Instruments Incorporated

3 Facility

VPT Rad performs all neutron displacement damage irradiations in a Low-Enriched, open-pool, water moderated, thermal neutron reactor. VPT Rad uses flat-plate type fuel, and having a maximum thermal energy output of up to 1MW. The Fast Neutron Irradiator (FNI) faces one side of the reactor core, the design produces a geometrical planar beam of fast neutrons that is approximately uniform over an area of 12in × 20in. Lead and thermal neutron absorbing compounds are combined to filter out both fission gammas and thermal neutrons. The ratio of fast-to-thermal neutrons is approximately 400:1, with a gamma exposure of less than 150rad (Si) for a 1E12 n/cm2 (1MeV Si equivalent) exposure. The FNI can accommodate a sample or samples with size up to 30cm in diameter and 15 cm thick including packaging materials. The minimum neutron fluence rate is 1E6 n/cm2-s. The maximum neutron fluence rate is approximately 1.0 E11 n/cm2-s. Both values are 1MeV Si equivalent.

The neutron fluence rate is determined using the previously measured neutron radiation field for the FNI, performed in accordance with ASTM standards (ASTM F1190), and correlated to the measured reactor power level. The neutron dose is timed to meet the customer-specified fluence for the irradiation. Neutron dosimetry meeting ASTM standards (ASTM E265) is used to track and verify irradiations meet the required minimum. The facility retains source-suitability with the Defense Logistics Agency (DLA) Laboratory Suitability Program for ASTM Test Method 1017. The DUTS are typically irradiation in an unbiased condition as per TM1017. If bias conditions are required, the conditions can be maintained through dry thimbles connected to the irradiation volume.

Copyright © 2026 Texas Instruments Incorporated

4 Results

The data presented below represent the measured parameter values recorded throughout the test. All of the parameters passed the functional tests and remained within the specified limits. The full parameter list is shown in Section 4.1 and the related data can be found in Appendix A.

Specifications are at ambient temperature TA = 25°C, PVIN=VIN= 4.5V to 14V unless otherwise noted. Parameters not listed in the table are omitted either because there is no parametric data or because verification was done through bench testing. Parameters without MIN and MAX values are functionally assured by ATE testing.

4.1 Data Sheet Electrical Parameters and Associated Tests

Table 4-1. Data Sheet Electrical Parameters

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
SUPPLY VOLTAGES AND CURRENTS							
IDD	Operating supply current	No load for OUT, PVIN = VIN	fSW = 100kHz		11	mA	14.1, 14.2, 14.3, 14.4
			fSW = 500kHz		17		14.6, 14.8, 14.10, 14.12
			fSW = 1MHz (TPS7H502x)		25		14.14, 14.15, 14.16, 14.17
		CLOAD = 1000pF for OUT, PVIN = VIN	fSW = 100kHz		12	mA	
			fSW = 500kHz		22		
			fSW = 1MHz		28		
		CLOAD = 1000pF for OUT, VIN = 12V, PVIN = VLDO = 5V	fSW = 100kHz		10	mA	14.3
			fSW = 500kHz		13		14.31
			fSW = 1MHz		20		14.32
Istart	Startup current	VIN = 3.5V			5	mA	14.5
IDD(dis)	Standby current	EN = 0V			8	mA	14.7, 14.9, 14.11, 14.13
VLDO	Internal linear regulator output voltage	CVLDO = 1µF	5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.74kΩ	4.36	4.62	V	15.1, 15.4, 15.5
			5.5V ≤ VIN ≤ 14V, RVT = 10kΩ, RVB = 3.24kΩ	4.84	5.14		15.8, 15.11, 15.12
			6V ≤ VIN ≤ 14V, RVT = 10 kΩ, RVB = 2.87kΩ	5.31	5.65		15.15, 15.18, 15.19
VLDO_DO	Internal linear dropout voltage	IVLDO = 25mA, CVLDO = 1µF			0.4	V	
I_VLDO	Maximum VLDO output current	VLDO ≥ 96% of VLDO at no load, CVLDO = 1µF	VIN = VLDO + 0.5V	25		mA	
			VIN = VLDO + 1V	55			
			VIN ≥ 7V	90			
ENABLE AND UNDERVOLTAGE LOCKOUT							

Copyright © 2026 Texas Instruments Incorporated

Table 4-1. Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
VENR	Enable rising threshold			0.57	0.66	V	16.1, 16.4, 16.7, 16.10
VENF	Enable falling threshold			0.48	0.55	V	16.2, 16.5, 16.8, 16.11
IEN	Enable input leakage current	VIN = 14V	EN = 1V		100	nA	16.15, 16.17
			EN = 7V		700		16.16, 16.18
PVINUVLOR	PVIN UVLO rising			3.65	3.95	V	17.1, 17.10, 17.19
PVINUVLOF	PVIN UVLO falling			3.45	3.75	V	17.2, 17.11, 17.20
VINUVLOR	VIN UVLO rising			3.85	4.15	V	17.4, 17.13, 17.22
VINUVLOF	VIN UVLO falling			3.65	3.95	V	17.5, 17.14, 17.23
VLDOUVLOR	VLDO UVLO rising			3.65	3.95	V	17.7, 17.16, 17.25
VLDOUVLOF	VLDO UVLO falling			3.45	3.75	V	17.8, 17.17, 17.26
SOFT START							
ISS	Soft-start current	SS = 0.3V		2	3.4	µA	18.1, 18.5, 18.9, 18.13, 18.17, 18.21, 18.25, 18.29, 18.33, 18.37, 18.41, 18.45
ERROR AMPLIFIER							
EAgm	Error amplifier transconductance	–10µA < ICOMP < 10µA, V(COMP) = 1V		1100	2700	µA/V	19.1, 19.5, 19.9, 19.13
EAISRC	Error amplifier source current	V(COMP) = 1V, 100mV input overdrive		95	210	µA	19.2, 19.6, 19.10, 19.14
EAISNK	Error amplifier sink current	V(COMP) = 1V, 100mV input overdrive		95	210	µA	19.3, 19.7, 19.11, 19.15
EAOS	Error amplifier input offset voltage			–5	6	mV	19.27, 19.30, 19.33, 19.36, 19.39, 19.42, 19.45, 19.48, 19.51, 19.54, 19.57, 19.60
EAIB	Error amplifier input bias current				25	nA	19.4, 19.8, 19.12, 19.16, 19.17, 19.18, 19.19, 19.20, 19.21, 19.22, 19.23, 19.24
OSCILLATOR							

Copyright © 2026 Texas Instruments Incorporated

Table 4-1. Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
SYNCIL	SYNC in low-level	VLDO = 4.5V	VIN < 5V		0.8	V	
			VIN ≥ 5V		0.8		
		VLDO = 5.5V	VIN < 6V		0.8	V	
			VIN ≥ 6V		0.8		
SYNCIH	SYNC in high-level	VLDO = 4.5V	VIN < 5V	3.5		V	
			VIN ≥ 5V	3.5			
		VLDO = 5.5V	VIN < 6V	3.5		V	
			VIN ≥ 6V	3.5			
DSYNC	SYNC in duty cycle	Duty cycle of external clock, f ≥ 200kHz		48%	52%		20.17, 20.18, 20.21, 20.22, 20.25, 20.26, 20.29, 20.30, 20.41, 20.42, 20.45, 20.46, 20.49, 20.50, 20.53, 20.54, 20.57, 20.58, 20.61, 20.62, 20.65, 20.66, 20.69, 20.70
		Duty cycle of external clock, 100kHz ≤ f < 200kHz		49%	51%		
DTINT	External clock to internal clock detection time	RT populated			5	(1/fsw) s	20.144, 20.146, 20.148, 20.150, 20.152, 20.154, 20.156, 20.158, 20.160, 20.162, 20.164, 20.166, 20.168, 20.170, 20.172, 20.174
DTEXT	Internal clock to external clock detection time	RT populated			5	(1/fsw) s	20.112, 20.114, 20.116, 20.118, 20.120, 20.122, 20.124, 20.126, 20.128, 20.130, 20.132, 20.134, 20.136, 20.138, 20.140, 20.142

Copyright © 2026 Texas Instruments Incorporated

Table 4-1. Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
fSW	RT programmed switching frequency	RT = 1.18MΩ		80	110	kHz	20.15, 20.19, 20.23, 20.27, 20.71, 20.73, 20.75, 20.77
		RT = 560kΩ		175	220	kHz	20.31, 20.33, 20.35, 20.37, 20.79, 20.81, 20.83, 20.85
		RT = 210kΩ		450	550	kHz	20.39, 20.43, 20.47, 20.51, 20.87, 20.89, 20.91, 20.93
fSW	RT programmed switching frequency	RT = 100kΩ		925	1100	kHz	20.55, 20.59, 20.63, 20.67, 20.95, 20.97, 20.99, 20.101
VOLTAGE REFERENCE							
VREF	Internal voltage reference	Measured at COMP, COMP = VSENSE	TA = 25°C	0.597	0.603	V	19.25, 19.28, 19.31, 19.34, 19.37, 19.40, 19.43, 19.46, 19.49, 19.52, 19.55, 19.58, 19.61, 19.63, 19.65, 19.67, 19.69, 19.71, 19.73, 19.75, 19.77, 19.79, 19.81, 19.83
			TA = –55°C	0.594	0.602		
			TA = 125°C	0.597	0.604		
REFCAP	REFCAP voltage	CREFCAP = 470nF		1.208	1.235	V	21.1, 21.3, 21.5, 21.7, 21.9, 21.11, 21.13, 21.15, 21.17, 21.19, 21.21, 21.23, 21.25, 21.27, 21.29, 21.31, 21.33, 21.35, 21.37, 21.39, 21.41, 21.43, 21.45, 21.47
CURRENT SENSE							
CCSR	COMP to CS_ILIM ratio	RSC = open		1.94	2.06		28.1, 28.2, 28.3, 28.4

Copyright © 2026 Texas Instruments Incorporated

Table 4-1. Data Sheet Electrical Parameters (continued)

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
VCS_ILIM	Current limit (overcurrent) threshold			0.96	1.04	V	28.9, 28.10, 28.11, 28.12, 28.13, 28.14, 28.15, 28.16, 28.17, 28.18, 28.19, 28.20
	CS_ILIM to OUT delay	CS_ILIM = 1V to 90% of OUT falling			115	ns	28.21, 28.22, 28.23, 28.24, 28.25, 28.26, 28.27, 28.28
GATE DRIVER							
VOL	Low-level voltage	IOL = 50mA			0.15	V	24.1, 24.3, 24.5, 24.7
PVIN - VOH	High-level voltage	IOH = 50mA			0.25	V	24.2, 24.4, 24.6, 24.8
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = PVIN = 4.5V		14	ns	24.9
			VIN = PVIN = 5V		14		24.11
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = PVIN = 12V		18	ns	24.13
			VIN = PVIN = 14V		20		24.15
tR_OUT	OUT rise time	CLOAD = 1000pF, 10% to 90%	VIN = 12V, PVIN = VLDO		16	ns	24.17, 24.19, 24.21
		CLOAD = 220pF, 10% to 90%	VIN = 12V, PVIN = VLDO		12	ns	24.23, 24.25, 24.27
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = PVIN = 4.5V		14	ns	24.1
			VIN = PVIN = 5V		14		24.12
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = PVIN = 12V		18	ns	24.14
			VIN = PVIN = 14V		18		24.16
tF_OUT	OUT fall time	CLOAD = 1000pF, 90% to 10%	VIN = 12V, PVIN = VLDO		14	ns	24.18, 24.20, 24.22
		CLOAD = 220pF, 90% to 10%	VIN = 12V, PVIN = VLDO		10	ns	24.24, 24.26, 24.28
ROH	Pull-up resistance	100mA from OUT			4.7	Ω	23.5, 23.7, 23.9, 23.11
ROL	Pull-down resistance	100mA into OUT			2.8	Ω	23.6, 23.8, 23.10, 23.12

Copyright © 2026 Texas Instruments Incorporated

Table 4-1. Data Sheet Electrical Parameters (continued)

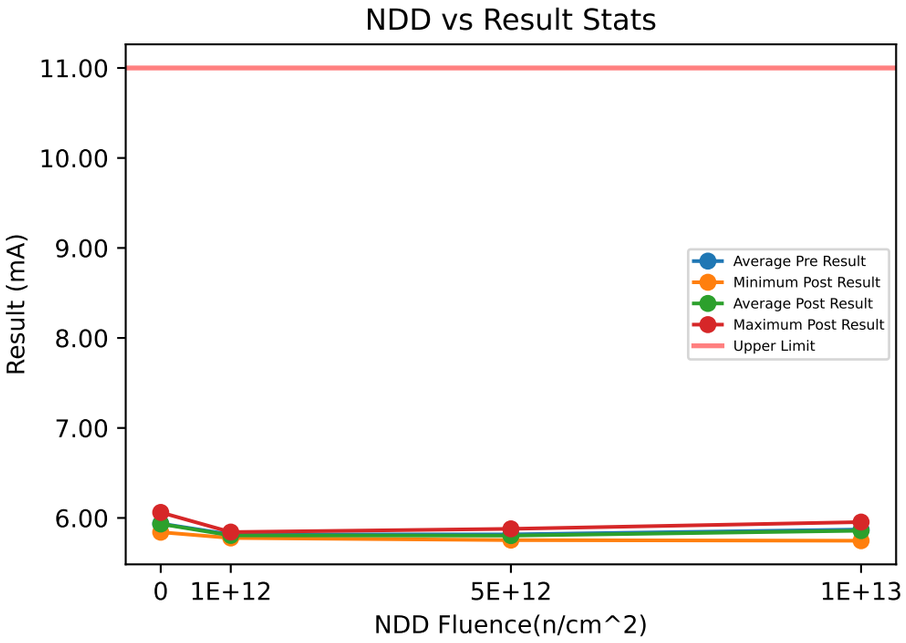
PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT	Test #
VUCLAMP	Unpowered OUT clamp voltage	Switching disabled, 1mA pull-up applied to OUT	PVIN = 0V		1	V	24.29
			0V < PVIN < 5V		2.5		24.3
PWM AND DUTY CYCLE							
TLEB	Leading edge blank time	5V ≤ VIN ≤ 14V, 10% of OUT rising to end of blanking			80	ns	25.1, 25.4, 25.7
ton_min	Minimum on-time(5)				165	ns	26.1, 26.2, 26.3, 26.4
toff_min	Minimum off-time				70	ns	26.5, 26.7
DMAX	Maximum duty cycle			42%	50%		27.17, 27.18, 27.19, 27.20, 27.21, 27.22, 27.23, 27.24, 27.25, 27.26, 27.27, 27.28, 27.29, 27.30, 27.31, 27.32, 27.33, 27.34, 27.35, 27.36, 27.37, 27.38, 27.39, 27.40, 27.41, 27.42, 27.43, 27.44, 27.45, 27.46, 27.47, 27.48

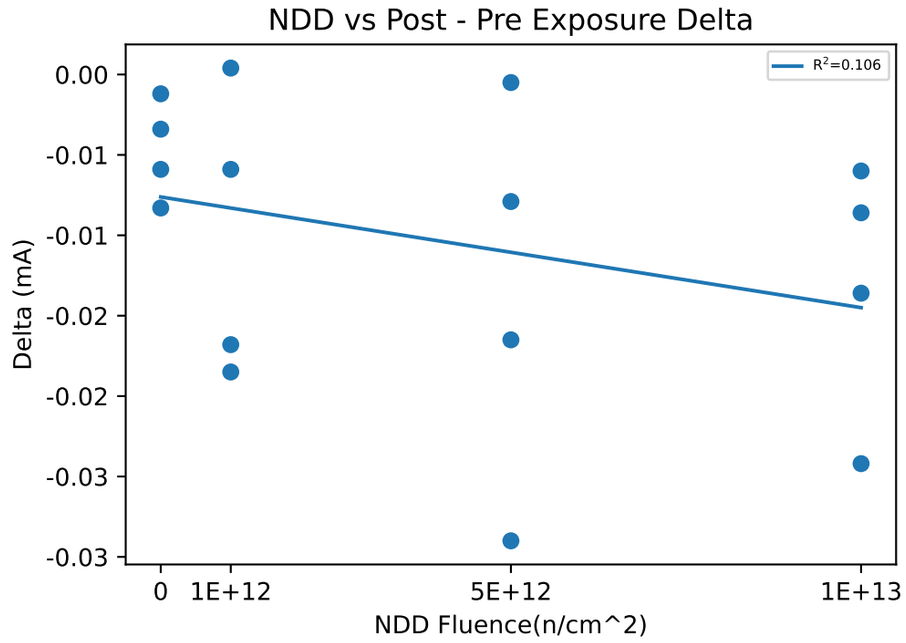
A Appendix: NDD Report Data

This appendix contains the detailed NDD test results.

Copyright © 2026 Texas Instruments Incorporated

Device Test: 14.1 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/100kHz//@IDD_ACT_100K_NOLOAD





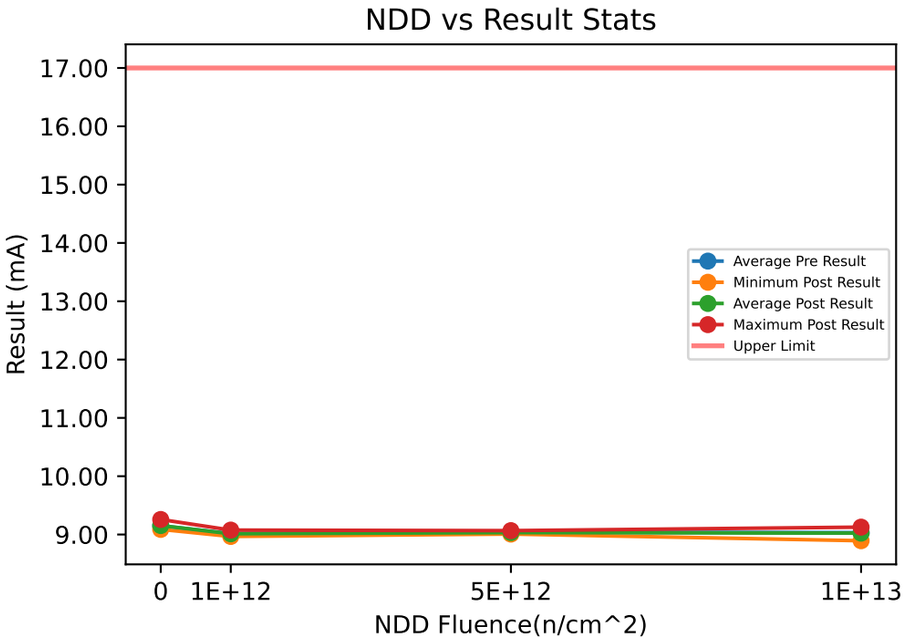
Test Results (Upper Limit = 11.0 (mA))

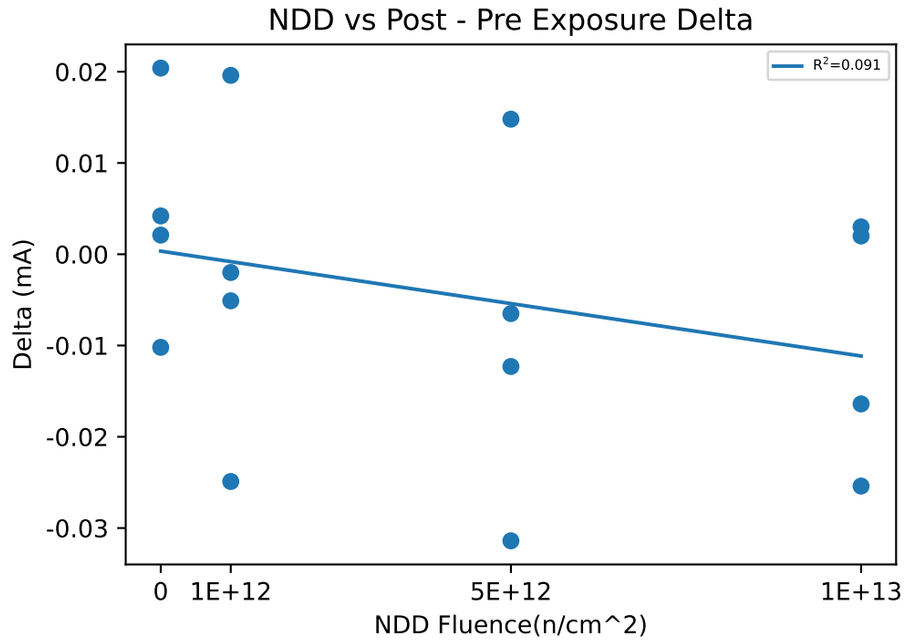
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.9029	5.8995	-0.0034
466	1e+12	NDD	5.8426	5.843	0.0004
762	0	CORRELATION	6.0672	6.0613	-0.0059
769	1e+12	NDD	5.7835	5.7776	-0.0059
887	1e+12	NDD	5.8135	5.7967	-0.0168
891	0	CORRELATION	5.9373	5.929	-0.0083
927	1e+12	NDD	5.8245	5.806	-0.0185
967	5e+12	NDD	5.7615	5.7536	-0.0079
1204	1e+13	NDD	5.81	5.7964	-0.0136
1284	1e+13	NDD	5.7712	5.747	-0.0242
1292	5e+12	NDD	5.9079	5.8789	-0.029
1364	1e+13	NDD	5.9444	5.9358	-0.0086
1383	5e+12	NDD	5.796	5.7795	-0.0165
1388	5e+12	NDD	5.8042	5.8037	-0.0005
1427	1e+13	NDD	5.9601	5.9541	-0.006
1666	0	CORRELATION	5.8426	5.8414	-0.0012

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.8426	5.9375	6.0672	0.094913	5.8414	5.9328	6.0613	0.093076	-0.0083	-0.0047	-0.0012	0.0030735
1e+12	5.7835	5.816	5.8426	0.024781	5.7776	5.8058	5.843	0.027459	-0.0185	-0.0102	0.0004	0.0090056
5e+12	5.7615	5.8174	5.9079	0.063106	5.7536	5.8039	5.8789	0.054008	-0.029	-0.013475	-0.0005	0.012242
1e+13	5.7712	5.8714	5.9601	0.09488	5.747	5.8583	5.9541	0.10231	-0.0242	-0.0131	-0.006	0.008044

Device Test: 14.10 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





Test Results (Upper Limit = 17.0 (mA))

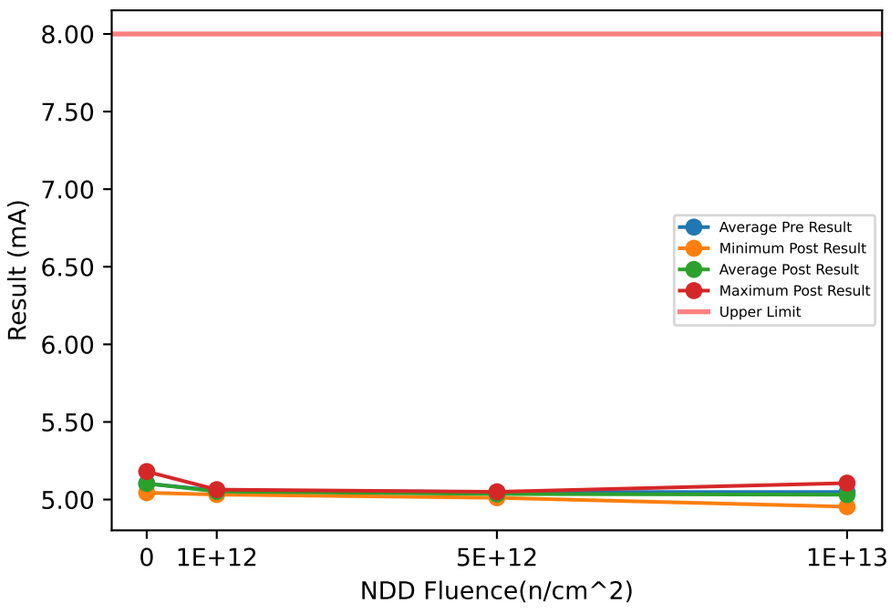
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	9.1053	9.1257	0.0204
466	1e+12	NDD	9.0562	9.0758	0.0196
762	0	CORRELATION	9.2536	9.2578	0.0042
769	1e+12	NDD	8.9689	8.9669	-0.002
887	1e+12	NDD	9.0121	8.9872	-0.0249
891	0	CORRELATION	9.1545	9.1443	-0.0102
927	1e+12	NDD	9.0264	9.0213	-0.0051
967	5e+12	NDD	9.0339	9.0274	-0.0065
1204	1e+13	NDD	9.0192	9.0028	-0.0164
1284	1e+13	NDD	8.919	8.8936	-0.0254
1292	5e+12	NDD	9.0979	9.0665	-0.0314
1364	1e+13	NDD	9.1244	9.1264	0.002
1383	5e+12	NDD	9.0437	9.0314	-0.0123
1388	5e+12	NDD	8.993	9.0078	0.0148
1427	1e+13	NDD	9.0681	9.0711	0.003
1666	0	CORRELATION	9.0858	9.0879	0.0021

Test Statistics (mA)

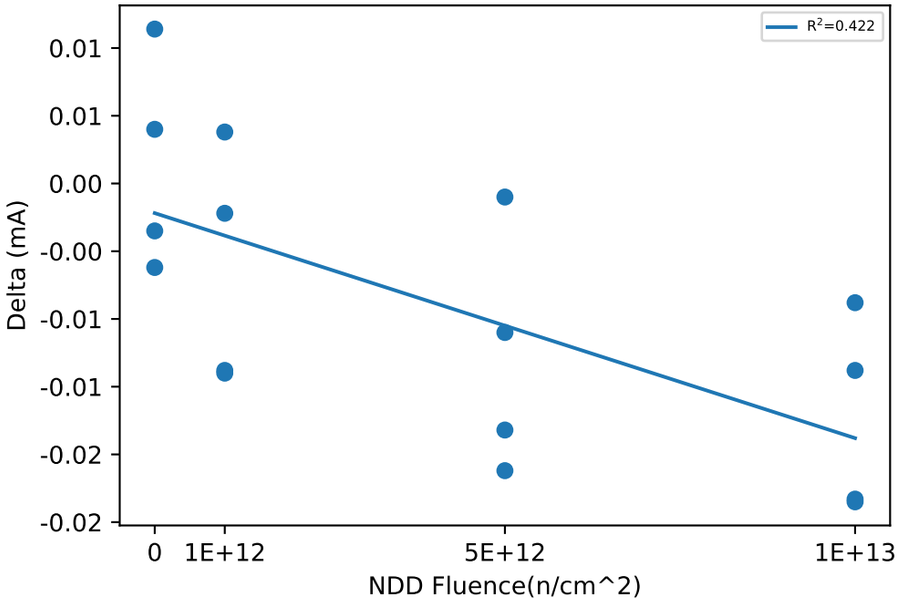
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.0858	9.1498	9.2536	0.074995	9.0879	9.1539	9.2578	0.073118	-0.0102	0.004125	0.0204	0.012572
1e+12	8.9689	9.0159	9.0562	0.036322	8.9669	9.0128	9.0758	0.047621	-0.0249	-0.0031	0.0196	0.018218
5e+12	8.993	9.0421	9.0979	0.043183	9.0078	9.0333	9.0665	0.024433	-0.0314	-0.00885	0.0148	0.01902
1e+13	8.919	9.0327	9.1244	0.087124	8.8936	9.0235	9.1264	0.10026	-0.0254	-0.0092	0.003	0.014007

Device Test: 14.11 IDD_DIS|STANDBY CURRENT/IN/12/12/0/0/5/500kHz//@IDD_DIS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



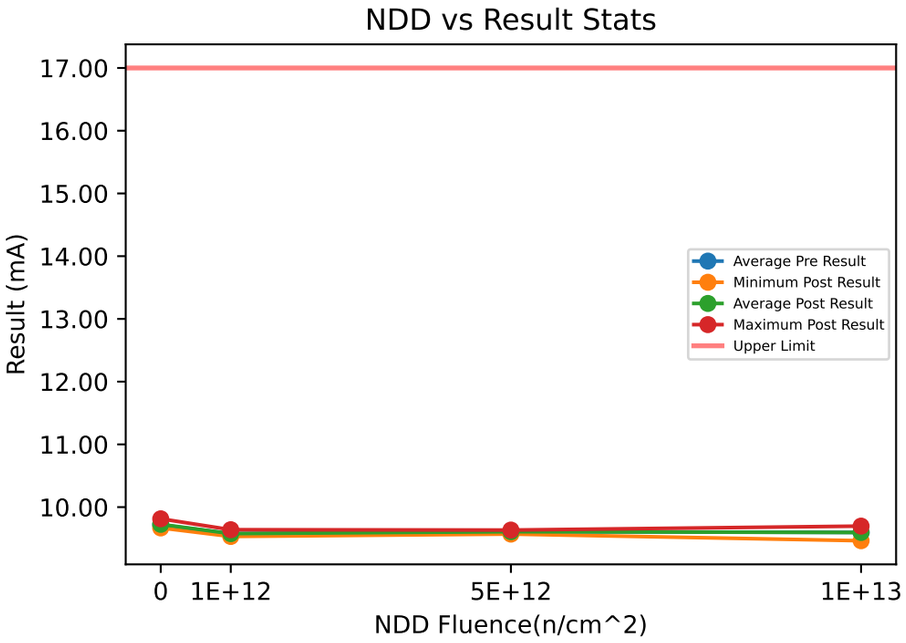
Test Results (Upper Limit = 8.0 (mA))

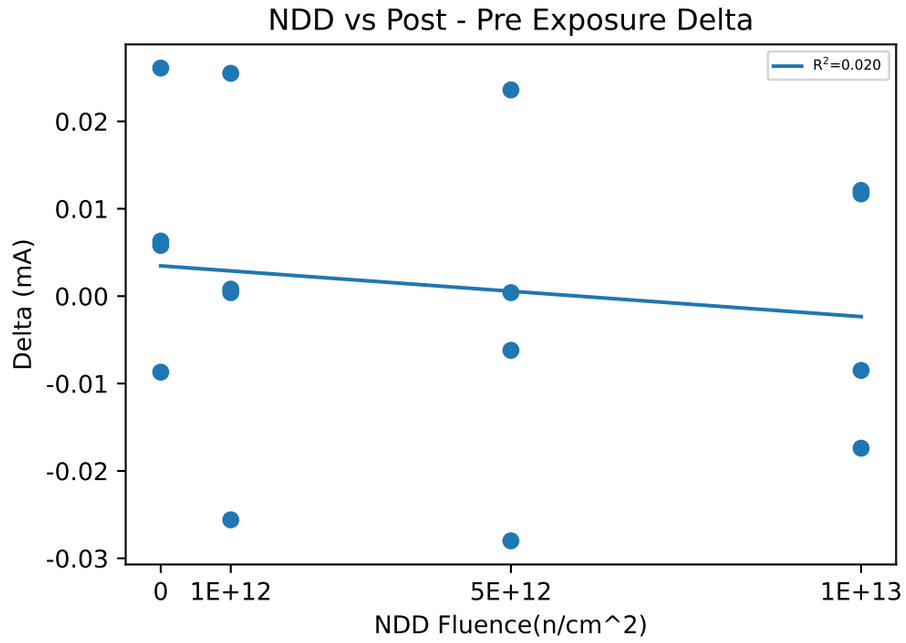
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.0851	5.0965	0.0114
466	1e+12	NDD	5.0517	5.0555	0.0038
762	0	CORRELATION	5.1839	5.1804	-0.0035
769	1e+12	NDD	5.0344	5.0322	-0.0022
887	1e+12	NDD	5.0777	5.0639	-0.0138
891	0	CORRELATION	5.1007	5.0945	-0.0062
927	1e+12	NDD	5.07	5.056	-0.014
967	5e+12	NDD	5.0434	5.0324	-0.011
1204	1e+13	NDD	5.0489	5.0256	-0.0233
1284	1e+13	NDD	4.9773	4.9538	-0.0235
1292	5e+12	NDD	5.071	5.0498	-0.0212
1364	1e+13	NDD	5.1147	5.1059	-0.0088
1383	5e+12	NDD	5.0677	5.0495	-0.0182
1388	5e+12	NDD	5.0122	5.0112	-0.001
1427	1e+13	NDD	5.0533	5.0395	-0.0138
1666	0	CORRELATION	5.0398	5.0438	0.004

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0398	5.1024	5.1839	0.060175	5.0438	5.1038	5.1804	0.05659	-0.0062	0.001425	0.0114	0.0079273
1e+12	5.0344	5.0585	5.0777	0.01939	5.0322	5.0519	5.0639	0.013685	-0.014	-0.00655	0.0038	0.0088338
5e+12	5.0122	5.0486	5.071	0.027194	5.0112	5.0357	5.0498	0.018261	-0.0212	-0.01285	-0.001	0.008985
1e+13	4.9773	5.0485	5.1147	0.056199	4.9538	5.0312	5.1059	0.062373	-0.0235	-0.01735	-0.0088	0.0072785

Device Test: 14.12 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





Test Results (Upper Limit = 17.0 (mA))

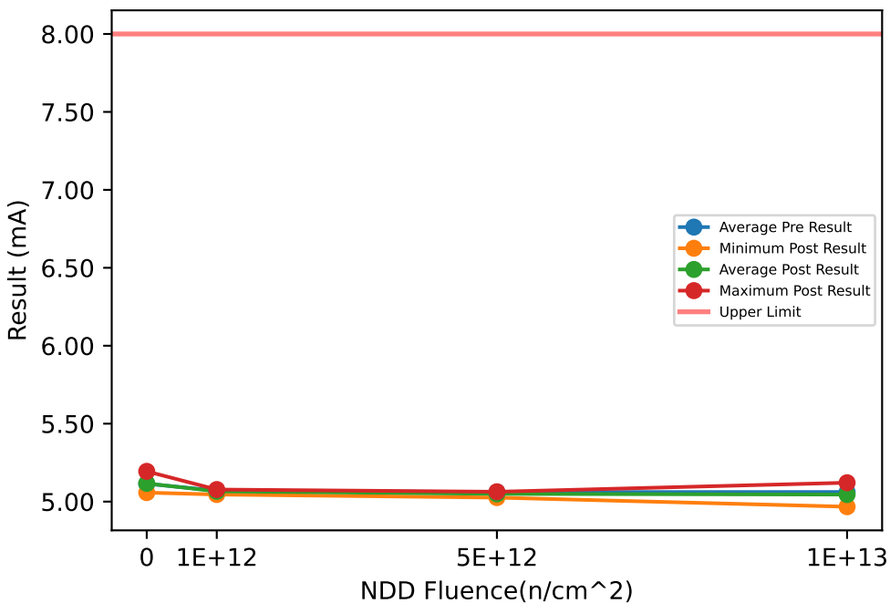
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	9.6809	9.707	0.0261
466	1e+12	NDD	9.6142	9.6397	0.0255
762	0	CORRELATION	9.8074	9.8137	0.0063
769	1e+12	NDD	9.5314	9.5322	0.0008
887	1e+12	NDD	9.5708	9.5452	-0.0256
891	0	CORRELATION	9.7232	9.7145	-0.0087
927	1e+12	NDD	9.5926	9.593	0.0004
967	5e+12	NDD	9.6203	9.6207	0.0004
1204	1e+13	NDD	9.5939	9.5854	-0.0085
1284	1e+13	NDD	9.4817	9.4643	-0.0174
1292	5e+12	NDD	9.6622	9.6342	-0.028
1364	1e+13	NDD	9.6854	9.6971	0.0117
1383	5e+12	NDD	9.6138	9.6076	-0.0062
1388	5e+12	NDD	9.5464	9.57	0.0236
1427	1e+13	NDD	9.6239	9.636	0.0121
1666	0	CORRELATION	9.6623	9.6681	0.0058

Test Statistics (mA)

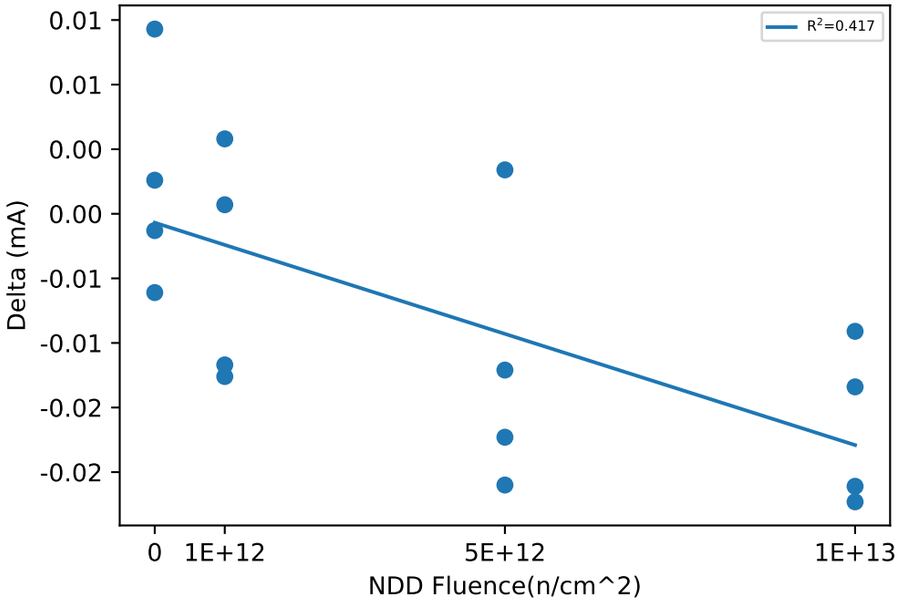
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.6623	9.7185	9.8074	0.064543	9.6681	9.7258	9.8137	0.062013	-0.0087	0.007375	0.0261	0.014291
1e+12	9.5314	9.5772	9.6142	0.035331	9.5322	9.5775	9.6397	0.049005	-0.0256	0.000275	0.0255	0.020866
5e+12	9.5464	9.6107	9.6622	0.047918	9.57	9.6081	9.6342	0.02764	-0.028	-0.00255	0.0236	0.021241
1e+13	9.4817	9.5962	9.6854	0.085322	9.4643	9.5957	9.6971	0.09879	-0.0174	-0.000525	0.0121	0.014801

Device Test: 14.13 IDD_DIS|STANDBY CURRENT/IN/14/14/0/0/5/500kHz//@IDD_DIS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



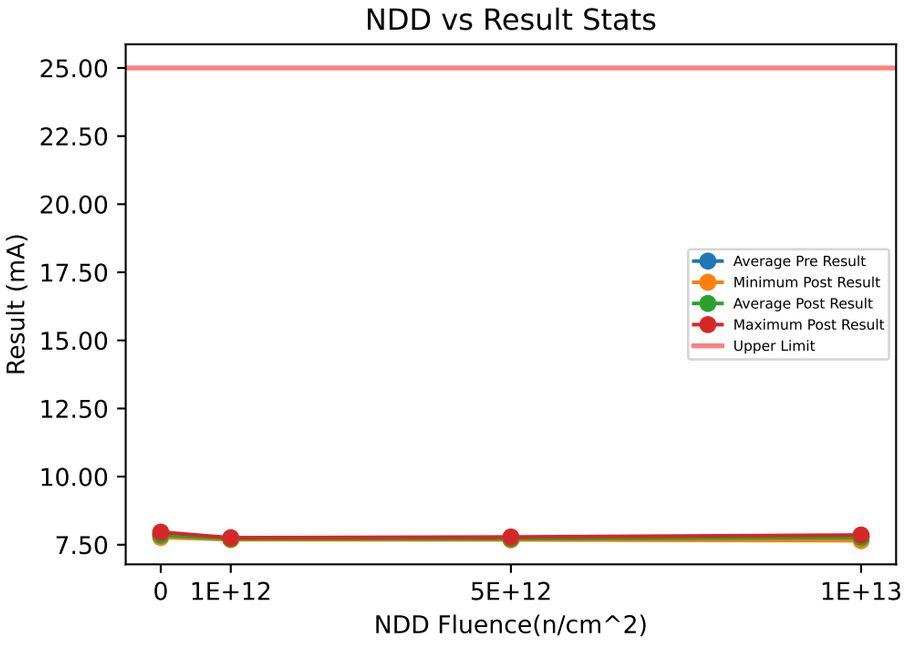
Test Results (Upper Limit = 8.0 (mA))

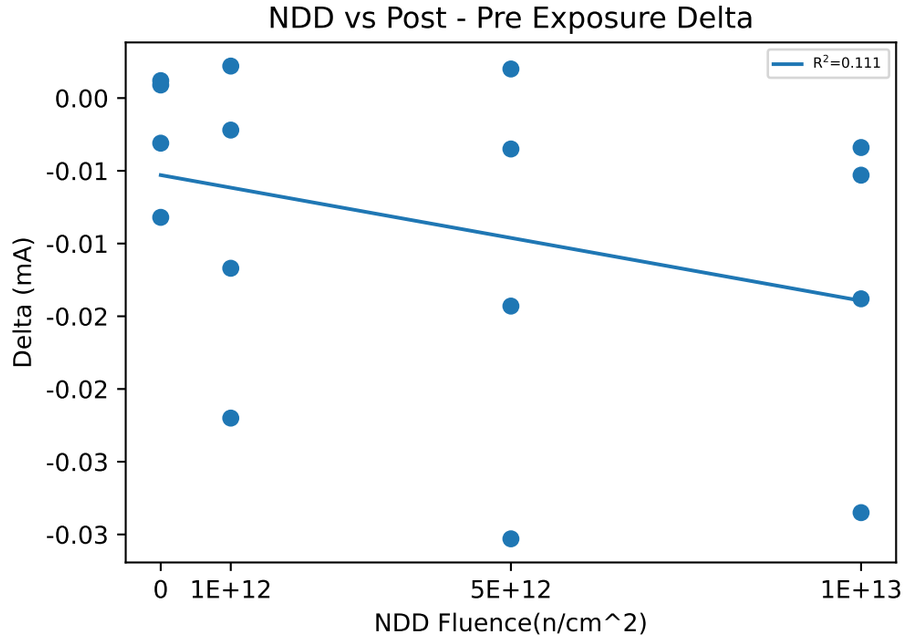
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.0951	5.1094	0.0143
466	1e+12	NDD	5.062	5.0678	0.0058
762	0	CORRELATION	5.1954	5.1941	-0.0013
769	1e+12	NDD	5.0448	5.0455	0.0007
887	1e+12	NDD	5.09	5.0774	-0.0126
891	0	CORRELATION	5.1119	5.1058	-0.0061
927	1e+12	NDD	5.0846	5.0729	-0.0117
967	5e+12	NDD	5.0599	5.0478	-0.0121
1204	1e+13	NDD	5.0611	5.0388	-0.0223
1284	1e+13	NDD	4.9883	4.9672	-0.0211
1292	5e+12	NDD	5.0841	5.0631	-0.021
1364	1e+13	NDD	5.1302	5.1211	-0.0091
1383	5e+12	NDD	5.079	5.0617	-0.0173
1388	5e+12	NDD	5.0223	5.0257	0.0034
1427	1e+13	NDD	5.0669	5.0535	-0.0134
1666	0	CORRELATION	5.0552	5.0578	0.0026

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.0552	5.1144	5.1954	0.059004	5.0578	5.1168	5.1941	0.056663	-0.0061	0.002375	0.0143	0.0087099
1e+12	5.0448	5.0704	5.09	0.02091	5.0455	5.0659	5.0774	0.014154	-0.0126	-0.00445	0.0058	0.0091391
5e+12	5.0223	5.0613	5.0841	0.028024	5.0257	5.0496	5.0631	0.01735	-0.021	-0.01175	0.0034	0.010739
1e+13	4.9883	5.0616	5.1302	0.058044	4.9672	5.0451	5.1211	0.063126	-0.0223	-0.016475	-0.0091	0.0063026

Device Test: 14.14 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/1MHz//@IDD_ACT_1M_NOLOAD





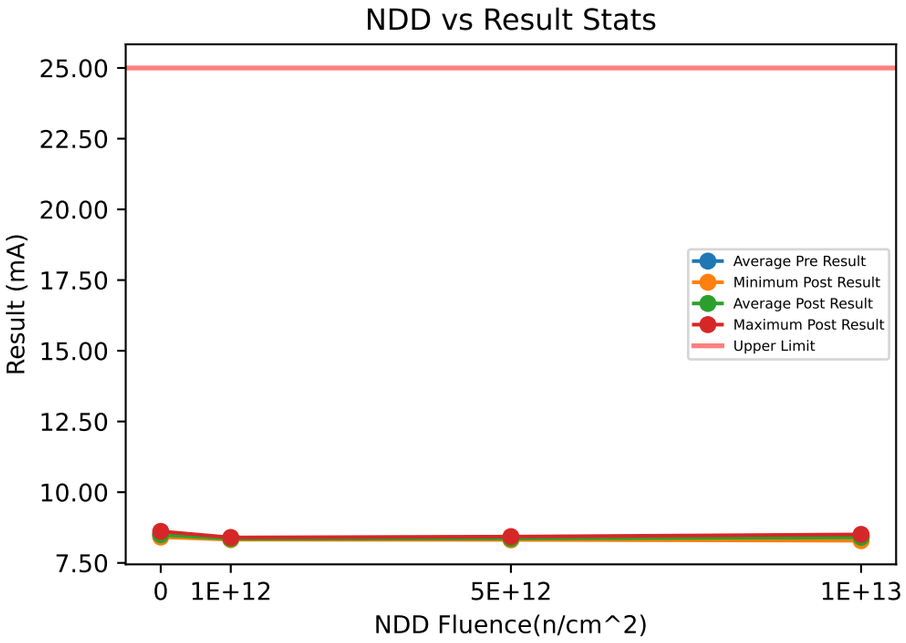
Test Results (Upper Limit = 25.0 (mA))

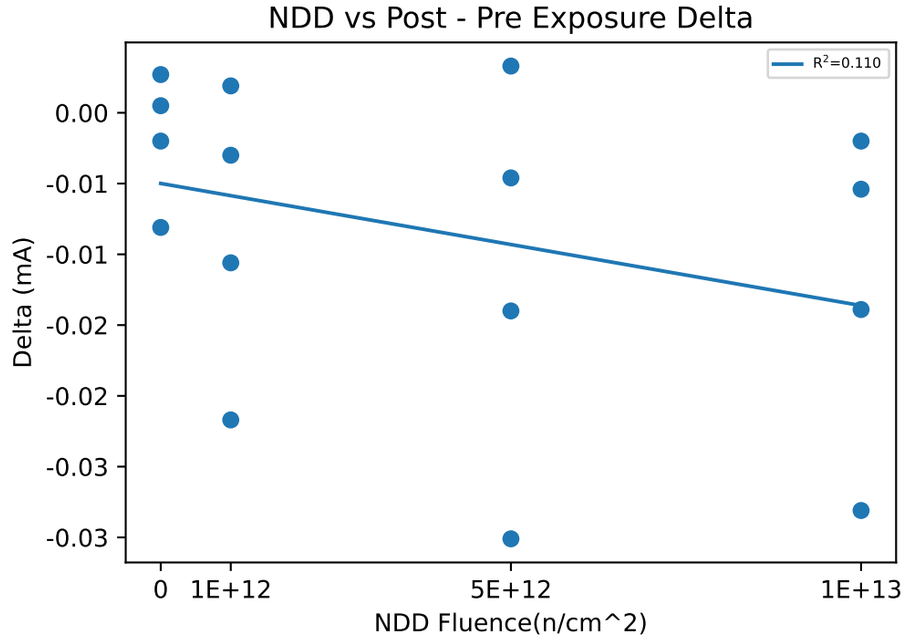
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.8131	7.8143	0.0012
466	1e+12	NDD	7.7548	7.757	0.0022
762	0	CORRELATION	7.966	7.9629	-0.0031
769	1e+12	NDD	7.6855	7.6833	-0.0022
887	1e+12	NDD	7.725	7.703	-0.022
891	0	CORRELATION	7.8511	7.8429	-0.0082
927	1e+12	NDD	7.7296	7.7179	-0.0117
967	5e+12	NDD	7.6804	7.6769	-0.0035
1204	1e+13	NDD	7.7148	7.701	-0.0138
1284	1e+13	NDD	7.6754	7.6469	-0.0285
1292	5e+12	NDD	7.8145	7.7842	-0.0303
1364	1e+13	NDD	7.8406	7.8353	-0.0053
1383	5e+12	NDD	7.7122	7.6979	-0.0143
1388	5e+12	NDD	7.7154	7.7174	0.002
1427	1e+13	NDD	7.8603	7.8569	-0.0034
1666	0	CORRELATION	7.7644	7.7653	0.0009

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.7644	7.8487	7.966	0.085905	7.7653	7.8464	7.9629	0.084048	-0.0082	-0.0023	0.0012	0.0043947
1e+12	7.6855	7.7237	7.7548	0.028653	7.6833	7.7153	7.757	0.031203	-0.022	-0.008425	0.0022	0.010749
5e+12	7.6804	7.7306	7.8145	0.058106	7.6769	7.7191	7.7842	0.046444	-0.0303	-0.011525	0.002	0.014231
1e+13	7.6754	7.7728	7.8603	0.091476	7.6469	7.76	7.8569	0.1022	-0.0285	-0.01275	-0.0034	0.011432

Device Test: 14.15 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





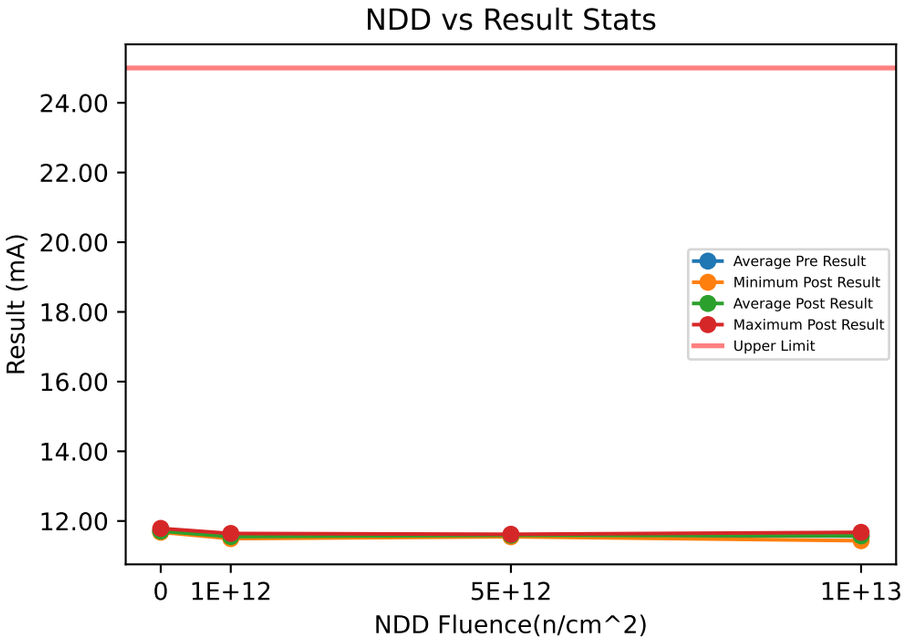
Test Results (Upper Limit = 25.0 (mA))

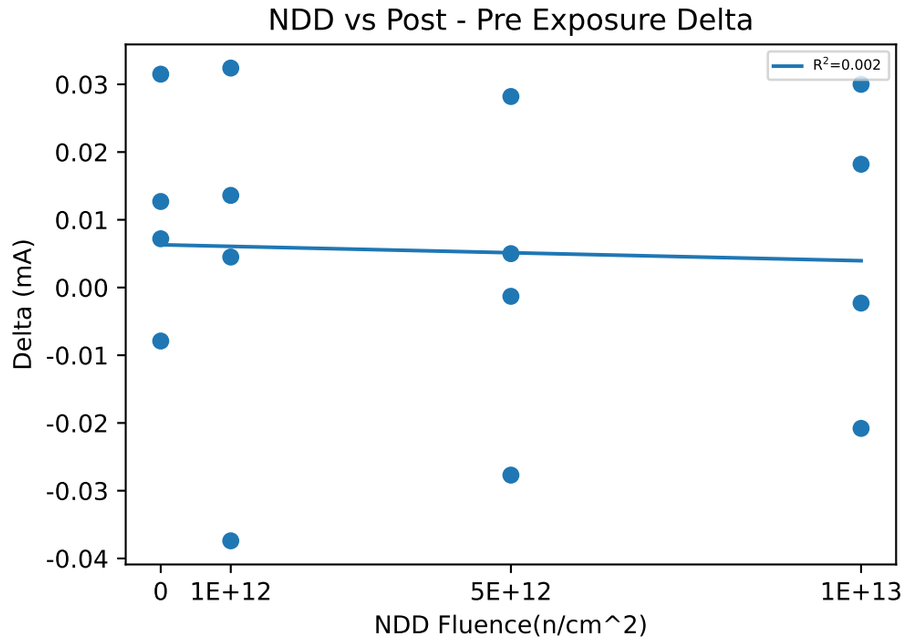
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	8.4574	8.4601	0.0027
466	1e+12	NDD	8.3976	8.3995	0.0019
762	0	CORRELATION	8.6175	8.6155	-0.002
769	1e+12	NDD	8.325	8.322	-0.003
887	1e+12	NDD	8.3619	8.3402	-0.0217
891	0	CORRELATION	8.5014	8.4933	-0.0081
927	1e+12	NDD	8.3673	8.3567	-0.0106
967	5e+12	NDD	8.319	8.3144	-0.0046
1204	1e+13	NDD	8.3559	8.342	-0.0139
1284	1e+13	NDD	8.3124	8.2843	-0.0281
1292	5e+12	NDD	8.4593	8.4292	-0.0301
1364	1e+13	NDD	8.4875	8.4821	-0.0054
1383	5e+12	NDD	8.3523	8.3383	-0.014
1388	5e+12	NDD	8.3596	8.3629	0.0033
1427	1e+13	NDD	8.5088	8.5068	-0.002
1666	0	CORRELATION	8.4107	8.4112	0.0005

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.4107	8.4968	8.6175	0.08861	8.4112	8.495	8.6155	0.087108	-0.0081	-0.001725	0.0027	0.0046636
1e+12	8.325	8.3629	8.3976	0.029782	8.322	8.3546	8.3995	0.033119	-0.0217	-0.00835	0.0019	0.010279
5e+12	8.319	8.3726	8.4593	0.060473	8.3144	8.3612	8.4292	0.049469	-0.0301	-0.01135	0.0033	0.014362
1e+13	8.3124	8.4162	8.5088	0.096728	8.2843	8.4038	8.5068	0.10776	-0.0281	-0.01235	-0.002	0.011632

Device Test: 14.16 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





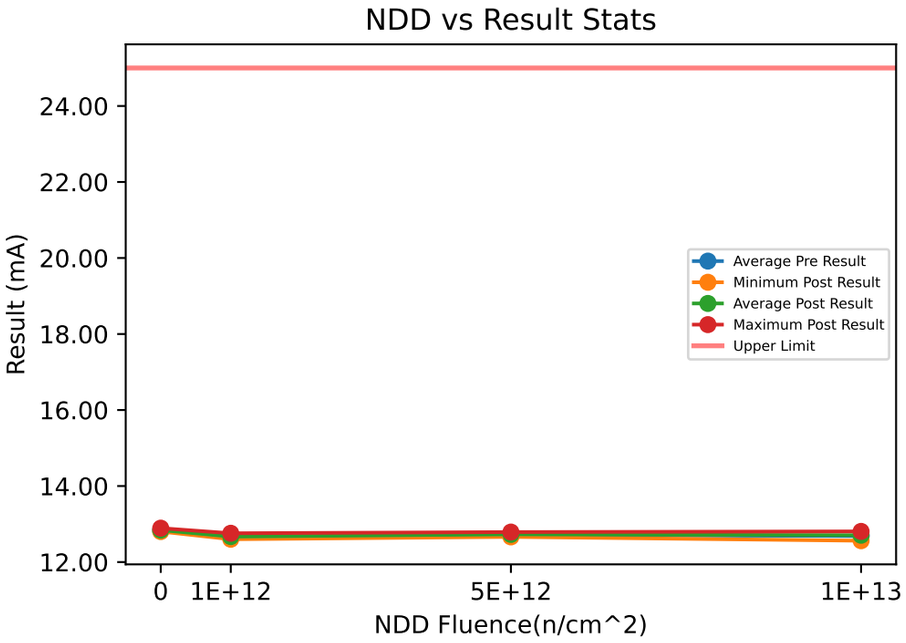
Test Results (Upper Limit = 25.0 (mA))

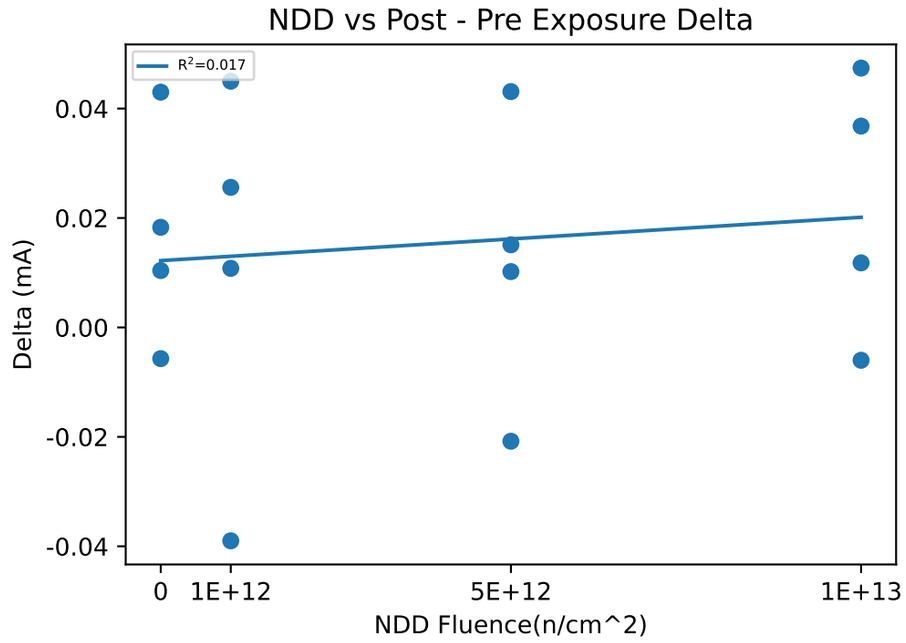
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	11.665	11.696	0.0315
466	1e+12	NDD	11.609	11.642	0.0324
762	0	CORRELATION	11.775	11.788	0.0127
769	1e+12	NDD	11.489	11.494	0.0045
887	1e+12	NDD	11.535	11.498	-0.0374
891	0	CORRELATION	11.686	11.678	-0.0079
927	1e+12	NDD	11.558	11.571	0.0136
967	5e+12	NDD	11.614	11.619	0.005
1204	1e+13	NDD	11.579	11.577	-0.0023
1284	1e+13	NDD	11.455	11.434	-0.0208
1292	5e+12	NDD	11.631	11.604	-0.0277
1364	1e+13	NDD	11.656	11.675	0.0182
1383	5e+12	NDD	11.6	11.598	-0.0013
1388	5e+12	NDD	11.519	11.548	0.0282
1427	1e+13	NDD	11.579	11.609	0.03
1666	0	CORRELATION	11.674	11.681	0.0072

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.665	11.7	11.775	0.050979	11.678	11.711	11.788	0.052132	-0.0079	0.010875	0.0315	0.016276
1e+12	11.489	11.548	11.609	0.049782	11.494	11.551	11.642	0.070001	-0.0374	0.003275	0.0324	0.0295
5e+12	11.519	11.591	11.631	0.049546	11.548	11.592	11.619	0.031019	-0.0277	0.00105	0.0282	0.022984
1e+13	11.455	11.567	11.656	0.083445	11.434	11.574	11.675	0.10161	-0.0208	0.006275	0.03	0.022447

Device Test: 14.17 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/1MHz//@IDD_ACT_1M_NOLOAD





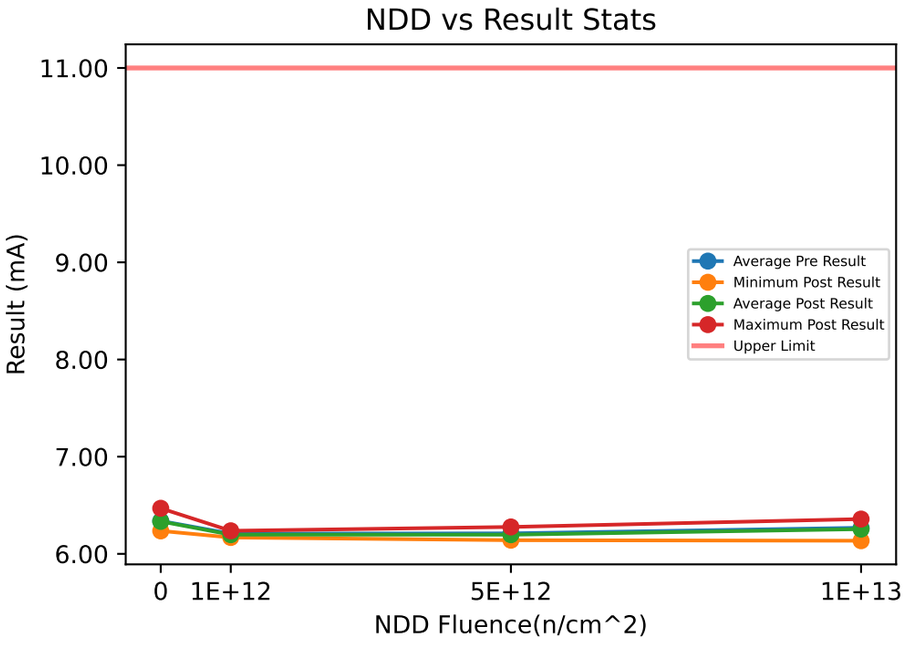
Test Results (Upper Limit = 25.0 (mA))

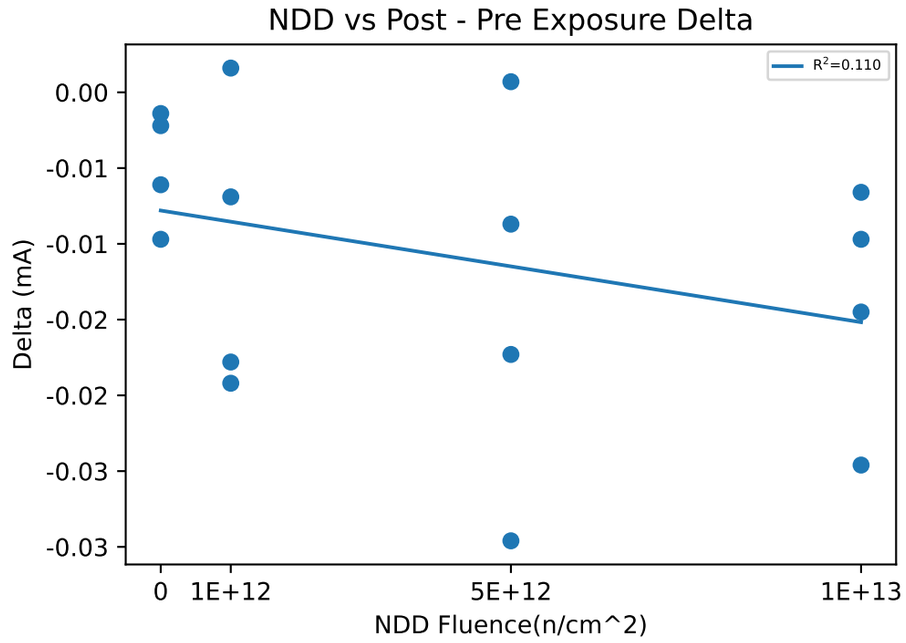
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	12.805	12.848	0.043
466	1e+12	NDD	12.713	12.758	0.045
762	0	CORRELATION	12.874	12.892	0.0183
769	1e+12	NDD	12.605	12.616	0.0108
887	1e+12	NDD	12.639	12.6	-0.039
891	0	CORRELATION	12.808	12.803	-0.0057
927	1e+12	NDD	12.679	12.704	0.0256
967	5e+12	NDD	12.774	12.789	0.0151
1204	1e+13	NDD	12.716	12.728	0.0118
1284	1e+13	NDD	12.567	12.561	-0.006
1292	5e+12	NDD	12.747	12.726	-0.0208
1364	1e+13	NDD	12.77	12.806	0.0368
1383	5e+12	NDD	12.726	12.736	0.0102
1388	5e+12	NDD	12.619	12.662	0.0431
1427	1e+13	NDD	12.681	12.728	0.0474
1666	0	CORRELATION	12.815	12.826	0.0104

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	12.805	12.825	12.874	0.032369	12.803	12.842	12.892	0.038096	-0.0057	0.0165	0.043	0.020294
1e+12	12.605	12.659	12.713	0.046728	12.6	12.669	12.758	0.074432	-0.039	0.0106	0.045	0.03591
5e+12	12.619	12.716	12.774	0.067819	12.662	12.728	12.789	0.052009	-0.0208	0.0119	0.0431	0.026178
1e+13	12.567	12.683	12.77	0.085596	12.561	12.706	12.806	0.10324	-0.006	0.0225	0.0474	0.024161

Device Test: 14.2 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





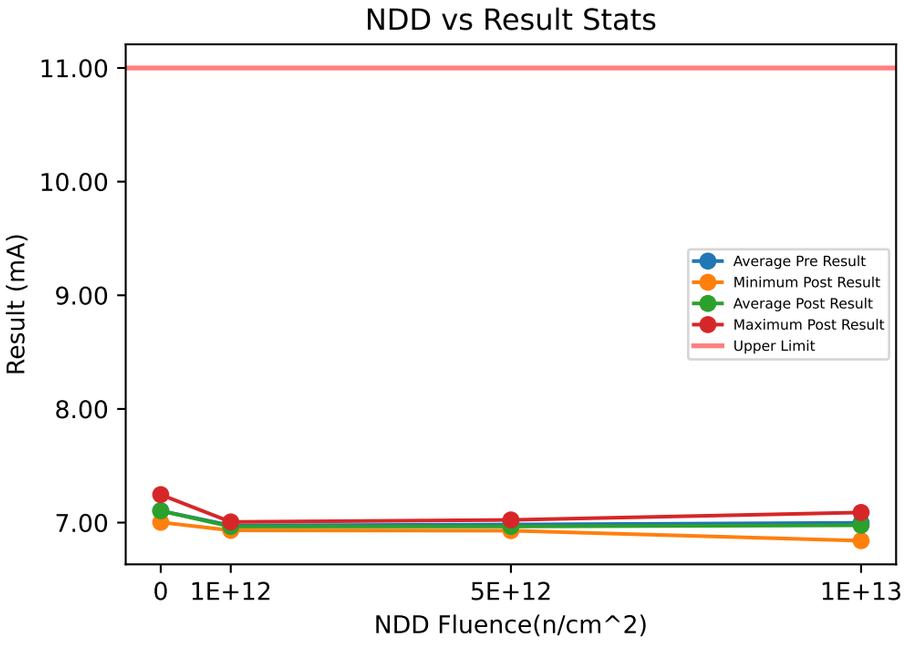
Test Results (Upper Limit = 11.0 (mA))

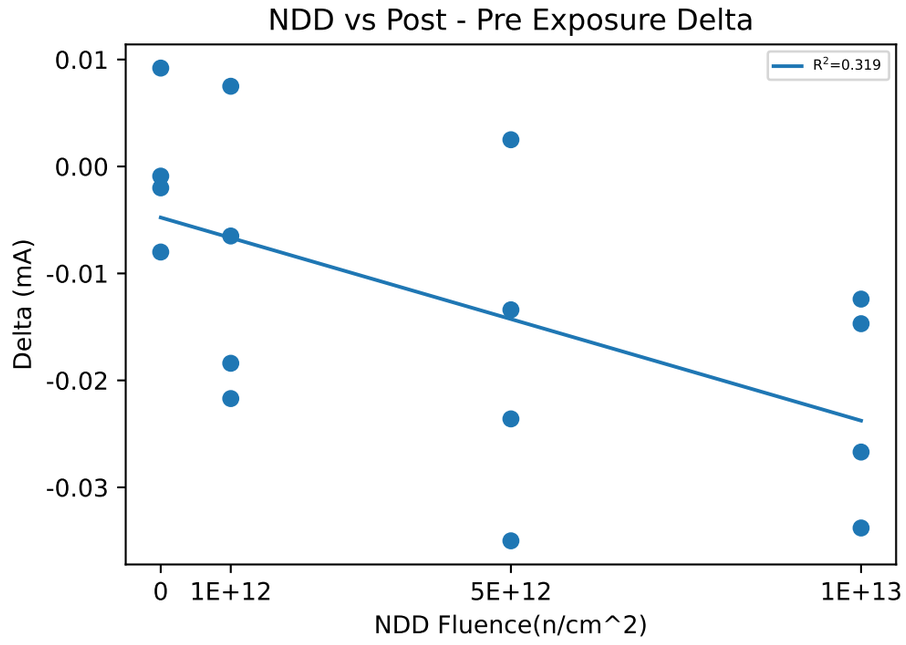
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	6.3009	6.2995	-0.0014
466	1e+12	NDD	6.2356	6.2372	0.0016
762	0	CORRELATION	6.475	6.4689	-0.0061
769	1e+12	NDD	6.1753	6.1684	-0.0069
887	1e+12	NDD	6.2037	6.1859	-0.0178
891	0	CORRELATION	6.3406	6.3309	-0.0097
927	1e+12	NDD	6.2173	6.1981	-0.0192
967	5e+12	NDD	6.1492	6.1405	-0.0087
1204	1e+13	NDD	6.202	6.1875	-0.0145
1284	1e+13	NDD	6.1597	6.1351	-0.0246
1292	5e+12	NDD	6.3063	6.2767	-0.0296
1364	1e+13	NDD	6.3465	6.3368	-0.0097
1383	5e+12	NDD	6.1863	6.169	-0.0173
1388	5e+12	NDD	6.2012	6.2019	0.0007
1427	1e+13	NDD	6.3645	6.3579	-0.0066
1666	0	CORRELATION	6.2383	6.2361	-0.0022

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.2383	6.3387	6.475	0.10015	6.2361	6.3338	6.4689	0.098289	-0.0097	-0.00485	-0.0014	0.0038301
1e+12	6.1753	6.208	6.2356	0.025404	6.1684	6.1974	6.2372	0.029199	-0.0192	-0.010575	0.0016	0.0098035
5e+12	6.1492	6.2107	6.3063	0.067348	6.1405	6.197	6.2767	0.058743	-0.0296	-0.013725	0.0007	0.012886
1e+13	6.1597	6.2682	6.3645	0.10257	6.1351	6.2543	6.3579	0.10986	-0.0246	-0.01385	-0.0066	0.0078691

Device Test: 14.3 IDD|SUPPLY CURRENT/IN/12/12/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





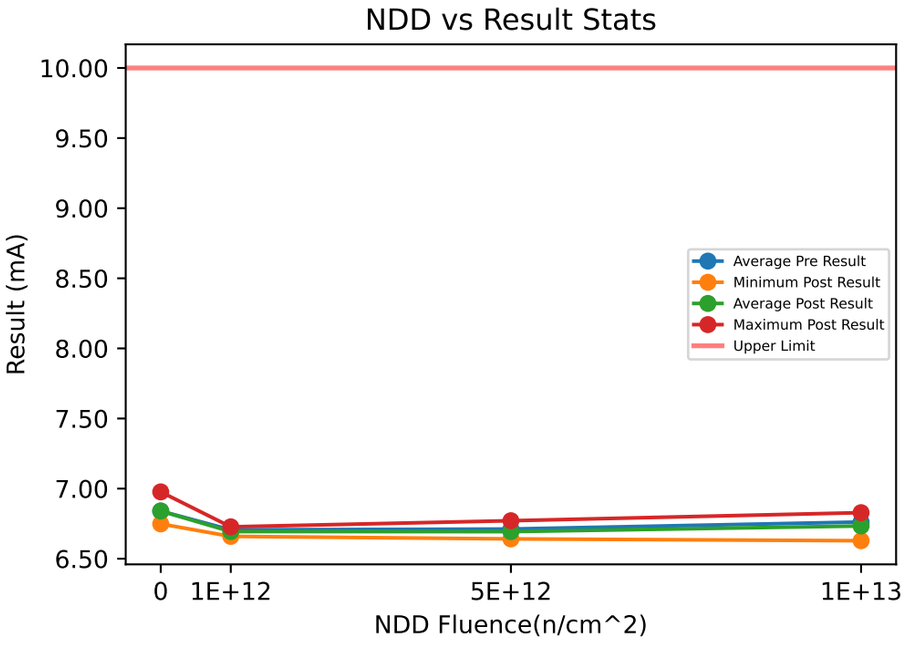
Test Results (Upper Limit = 11.0 (mA))

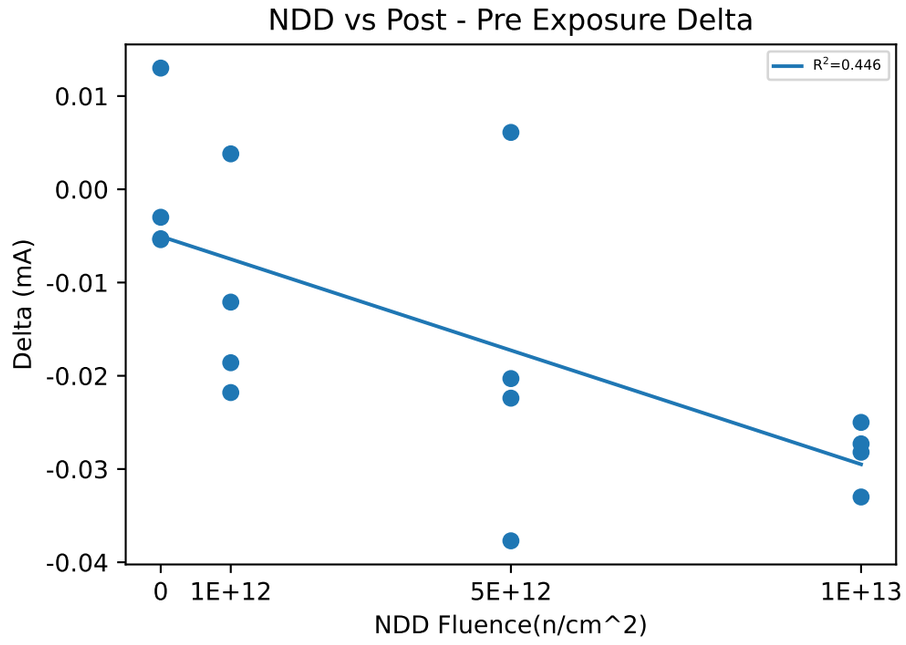
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.0548	7.064	0.0092
466	1e+12	NDD	6.9984	7.0059	0.0075
762	0	CORRELATION	7.248	7.246	-0.002
769	1e+12	NDD	6.9381	6.9316	-0.0065
887	1e+12	NDD	6.9767	6.955	-0.0217
891	0	CORRELATION	7.1094	7.1014	-0.008
927	1e+12	NDD	6.986	6.9676	-0.0184
967	5e+12	NDD	6.9423	6.9289	-0.0134
1204	1e+13	NDD	6.955	6.9283	-0.0267
1284	1e+13	NDD	6.8744	6.8406	-0.0338
1292	5e+12	NDD	7.0585	7.0235	-0.035
1364	1e+13	NDD	7.1016	7.0892	-0.0124
1383	5e+12	NDD	6.9698	6.9462	-0.0236
1388	5e+12	NDD	6.9619	6.9644	0.0025
1427	1e+13	NDD	7.0617	7.047	-0.0147
1666	0	CORRELATION	7.0034	7.0025	-0.0009

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.0034	7.1039	7.248	0.10537	7.0025	7.1035	7.246	0.1034	-0.008	-0.000425	0.0092	0.0071351
1e+12	6.9381	6.9748	6.9984	0.026031	6.9316	6.965	7.0059	0.031065	-0.0217	-0.009775	0.0075	0.013238
5e+12	6.9423	6.9831	7.0585	0.051563	6.9289	6.9657	7.0235	0.041138	-0.035	-0.017375	0.0025	0.015919
1e+13	6.8744	6.9982	7.1016	0.10314	6.8406	6.9763	7.0892	0.11323	-0.0338	-0.0219	-0.0124	0.010112

Device Test: 14.30 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/100kHz//@IDD_ACT_100K_LOAD_LDO





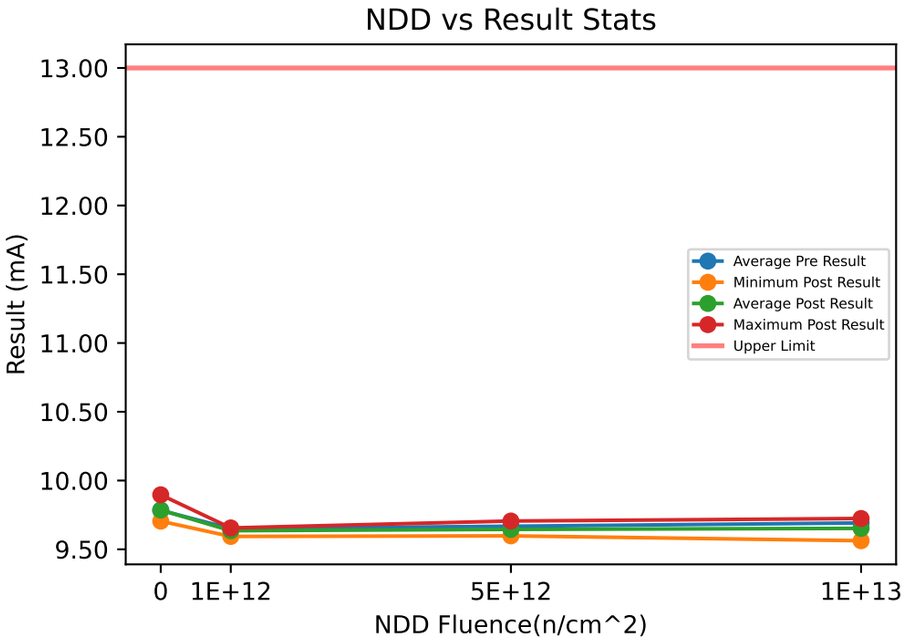
Test Results (Upper Limit = 10.0 (mA))

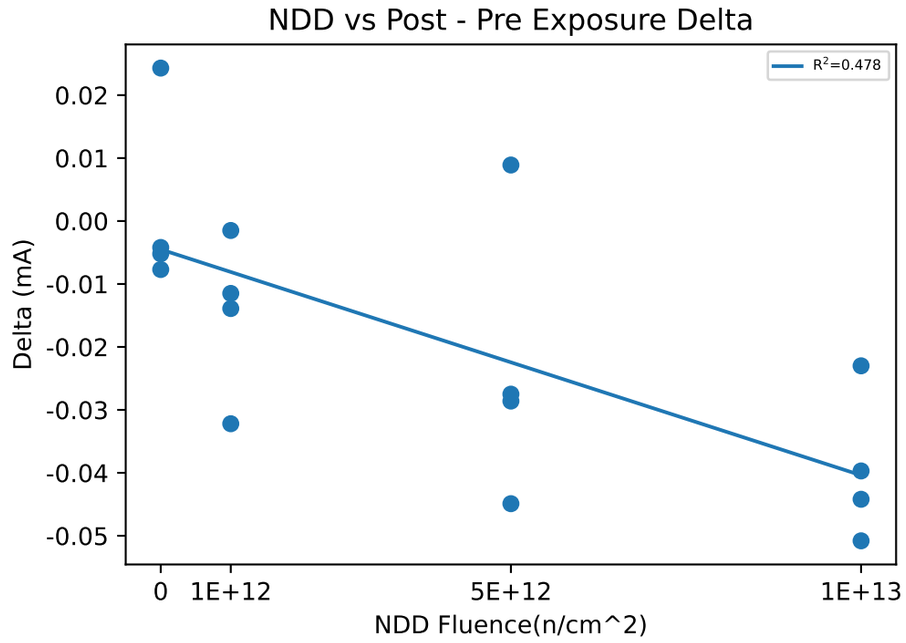
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	6.7714	6.7844	0.013
466	1e+12	NDD	6.7236	6.7274	0.0038
762	0	CORRELATION	6.9797	6.9767	-0.003
769	1e+12	NDD	6.6715	6.6594	-0.0121
887	1e+12	NDD	6.7133	6.6915	-0.0218
891	0	CORRELATION	6.8557	6.8503	-0.0054
927	1e+12	NDD	6.7155	6.6969	-0.0186
967	5e+12	NDD	6.6617	6.6414	-0.0203
1204	1e+13	NDD	6.6989	6.6707	-0.0282
1284	1e+13	NDD	6.6614	6.6284	-0.033
1292	5e+12	NDD	6.8087	6.771	-0.0377
1364	1e+13	NDD	6.8339	6.8066	-0.0273
1383	5e+12	NDD	6.6894	6.667	-0.0224
1388	5e+12	NDD	6.6877	6.6938	0.0061
1427	1e+13	NDD	6.8534	6.8284	-0.025
1666	0	CORRELATION	6.7537	6.7484	-0.0053

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7537	6.8401	6.9797	0.10314	6.7484	6.8399	6.9767	0.10046	-0.0054	-0.000175	0.013	0.008853
1e+12	6.6715	6.706	6.7236	0.023406	6.6594	6.6938	6.7274	0.027852	-0.0218	-0.012175	0.0038	0.011389
5e+12	6.6617	6.7119	6.8087	0.065783	6.6414	6.6933	6.771	0.056044	-0.0377	-0.018575	0.0061	0.018186
1e+13	6.6614	6.7619	6.8534	0.095961	6.6284	6.7335	6.8284	0.098893	-0.033	-0.028375	-0.025	0.0033649

Device Test: 14.31 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/500kHz//@IDD_ACT_500K_LOAD_LDO





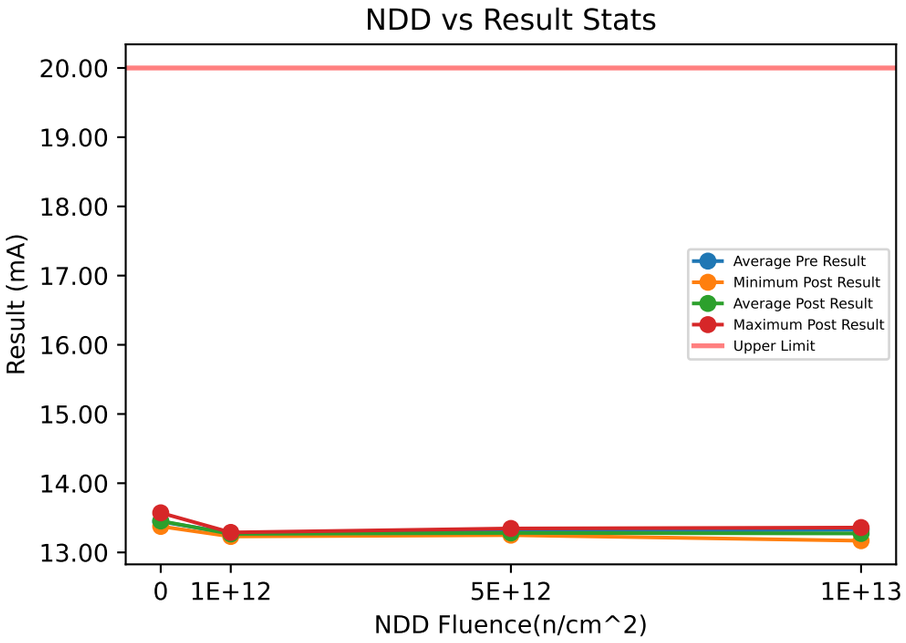
Test Results (Upper Limit = 13.0 (mA))

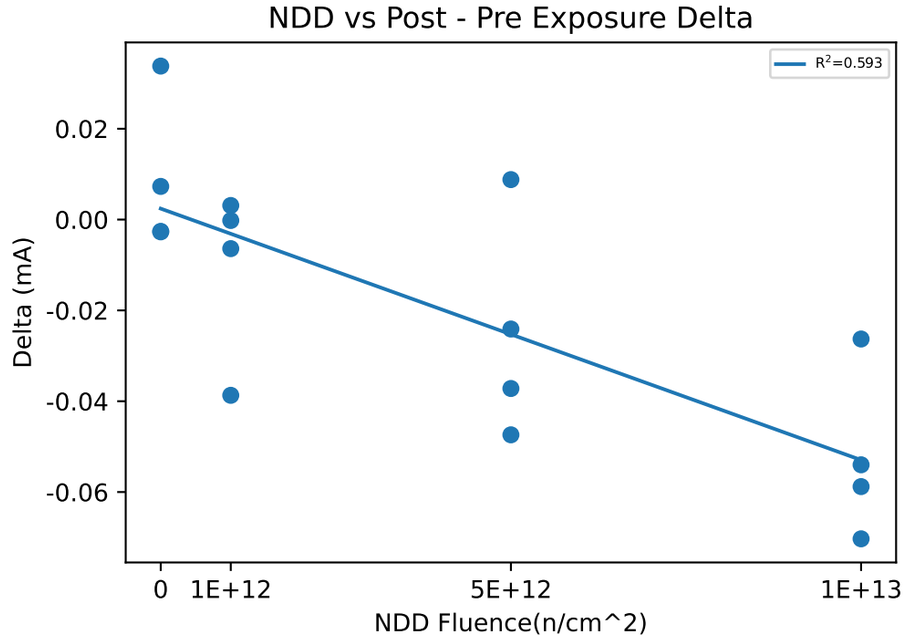
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	9.7021	9.7264	0.0243
466	1e+12	NDD	9.6568	9.6553	-0.0015
762	0	CORRELATION	9.9005	9.8963	-0.0042
769	1e+12	NDD	9.6051	9.5936	-0.0115
887	1e+12	NDD	9.6726	9.6404	-0.0322
891	0	CORRELATION	9.8228	9.8151	-0.0077
927	1e+12	NDD	9.666	9.6521	-0.0139
967	5e+12	NDD	9.6264	9.5978	-0.0286
1204	1e+13	NDD	9.6587	9.6145	-0.0442
1284	1e+13	NDD	9.6021	9.5624	-0.0397
1292	5e+12	NDD	9.7505	9.7056	-0.0449
1364	1e+13	NDD	9.7307	9.7077	-0.023
1383	5e+12	NDD	9.6611	9.6336	-0.0275
1388	5e+12	NDD	9.6332	9.6421	0.0089
1427	1e+13	NDD	9.7748	9.724	-0.0508
1666	0	CORRELATION	9.7097	9.7045	-0.0052

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.7021	9.7838	9.9005	0.095404	9.7045	9.7856	9.8963	0.087952	-0.0077	0.0018	0.0243	0.015072
1e+12	9.6051	9.6501	9.6726	0.030708	9.5936	9.6354	9.6553	0.028561	-0.0322	-0.014775	-0.0015	0.012798
5e+12	9.6264	9.6678	9.7505	0.057141	9.5978	9.6448	9.7056	0.044864	-0.0449	-0.023025	0.0089	0.022722
1e+13	9.6021	9.6916	9.7748	0.076472	9.5624	9.6522	9.724	0.076857	-0.0508	-0.039425	-0.023	0.011861

Device Test: 14.32 IDD|SUPPLY CURRENT/IN/5/12/0/1000/5/1MHz//@IDD_ACT_1M_LOAD_LDO





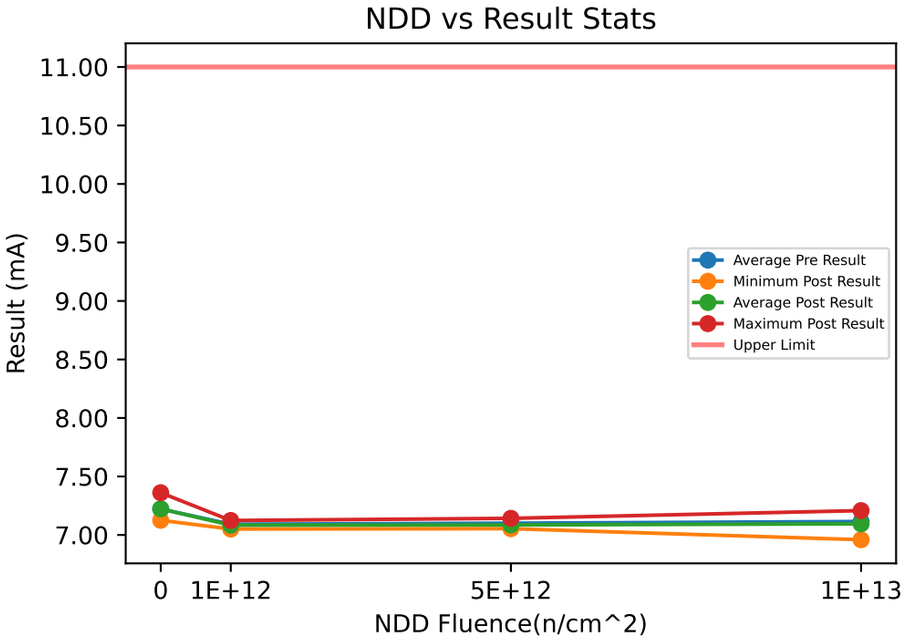
Test Results (Upper Limit = 20.0 (mA))

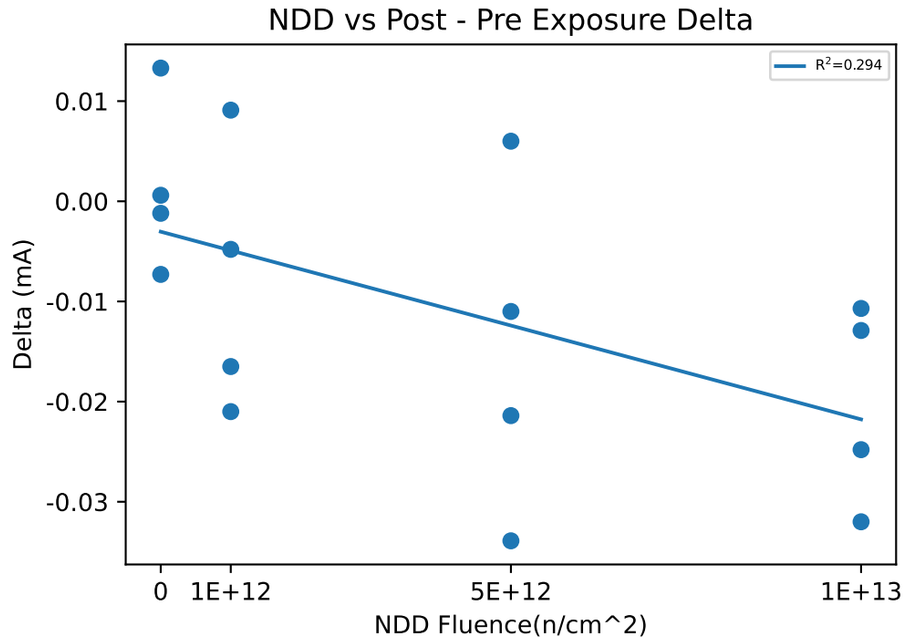
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	13.344	13.378	0.0338
466	1e+12	NDD	13.27	13.273	0.0031
762	0	CORRELATION	13.575	13.572	-0.0026
769	1e+12	NDD	13.231	13.23	-0.0002
887	1e+12	NDD	13.314	13.275	-0.0387
891	0	CORRELATION	13.494	13.491	-0.0027
927	1e+12	NDD	13.295	13.289	-0.0064
967	5e+12	NDD	13.274	13.249	-0.0241
1204	1e+13	NDD	13.299	13.24	-0.0588
1284	1e+13	NDD	13.223	13.169	-0.054
1292	5e+12	NDD	13.394	13.346	-0.0474
1364	1e+13	NDD	13.352	13.326	-0.0263
1383	5e+12	NDD	13.287	13.249	-0.0372
1388	5e+12	NDD	13.271	13.279	0.0088
1427	1e+13	NDD	13.43	13.359	-0.0703
1666	0	CORRELATION	13.368	13.376	0.0073

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	13.344	13.445	13.575	0.10847	13.376	13.454	13.572	0.095351	-0.0027	0.00895	0.0338	0.017218
1e+12	13.231	13.278	13.314	0.036129	13.23	13.267	13.289	0.025373	-0.0387	-0.01055	0.0031	0.019175
5e+12	13.271	13.306	13.394	0.058753	13.249	13.281	13.346	0.045623	-0.0474	-0.024975	0.0088	0.024453
1e+13	13.223	13.326	13.43	0.087068	13.169	13.274	13.359	0.085913	-0.0703	-0.05235	-0.0263	0.018665

Device Test: 14.4 IDD|SUPPLY CURRENT/IN/14/14/0/0/5/100kHz//@IDD_ACT_100K_NOLOAD





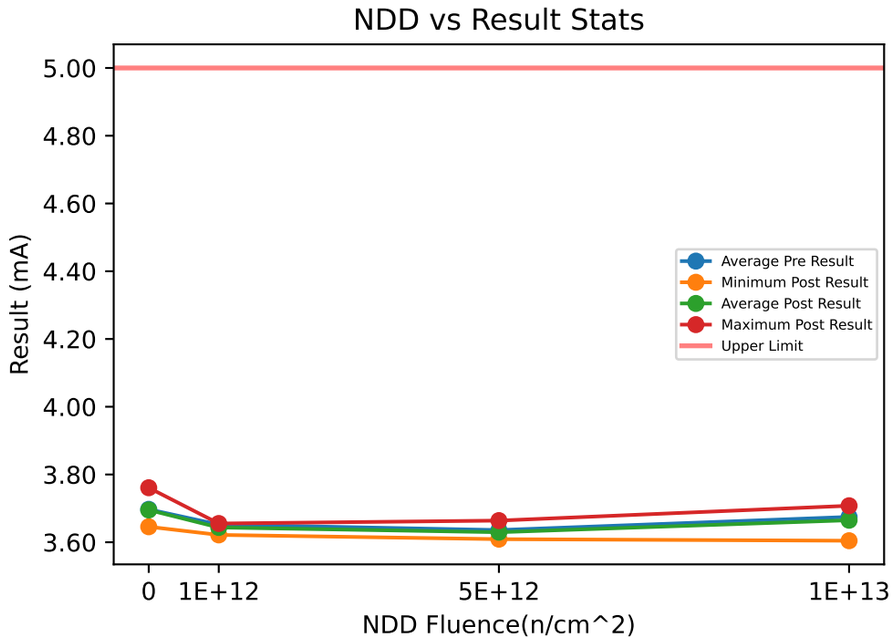
Test Results (Upper Limit = 11.0 (mA))

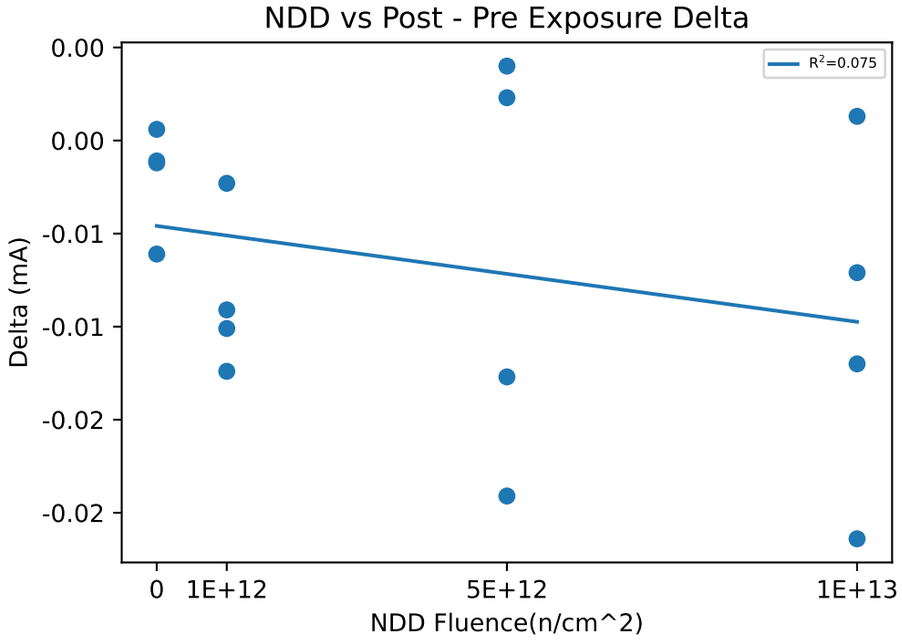
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.1721	7.1854	0.0133
466	1e+12	NDD	7.1147	7.1238	0.0091
762	0	CORRELATION	7.3624	7.3612	-0.0012
769	1e+12	NDD	7.0554	7.0506	-0.0048
887	1e+12	NDD	7.0936	7.0726	-0.021
891	0	CORRELATION	7.2283	7.221	-0.0073
927	1e+12	NDD	7.1037	7.0872	-0.0165
967	5e+12	NDD	7.0647	7.0537	-0.011
1204	1e+13	NDD	7.0732	7.0484	-0.0248
1284	1e+13	NDD	6.9913	6.9593	-0.032
1292	5e+12	NDD	7.1759	7.142	-0.0339
1364	1e+13	NDD	7.2188	7.2081	-0.0107
1383	5e+12	NDD	7.088	7.0666	-0.0214
1388	5e+12	NDD	7.0736	7.0796	0.006
1427	1e+13	NDD	7.1773	7.1644	-0.0129
1666	0	CORRELATION	7.1247	7.1253	0.0006

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1247	7.2219	7.3624	0.10281	7.1253	7.2232	7.3612	0.1001	-0.0073	0.00135	0.0133	0.0086543
1e+12	7.0554	7.0918	7.1147	0.025782	7.0506	7.0836	7.1238	0.030762	-0.021	-0.0083	0.0091	0.01346
5e+12	7.0647	7.1006	7.1759	0.051142	7.0537	7.0855	7.142	0.039139	-0.0339	-0.015075	0.006	0.016883
1e+13	6.9913	7.1151	7.2188	0.1028	6.9593	7.095	7.2081	0.11283	-0.032	-0.0201	-0.0107	0.010065

Device Test: 14.5 ISTART|STARTUP CURRENT/IN/3.5/3.5/0/0/4.5/500kHz//@I_START





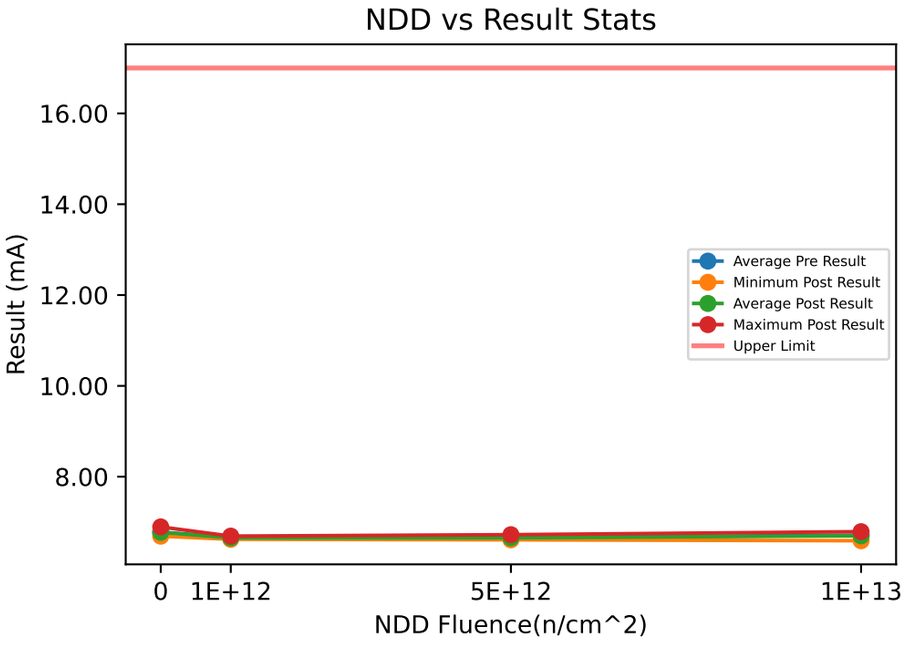
Test Results (Upper Limit = 5.0 (mA))

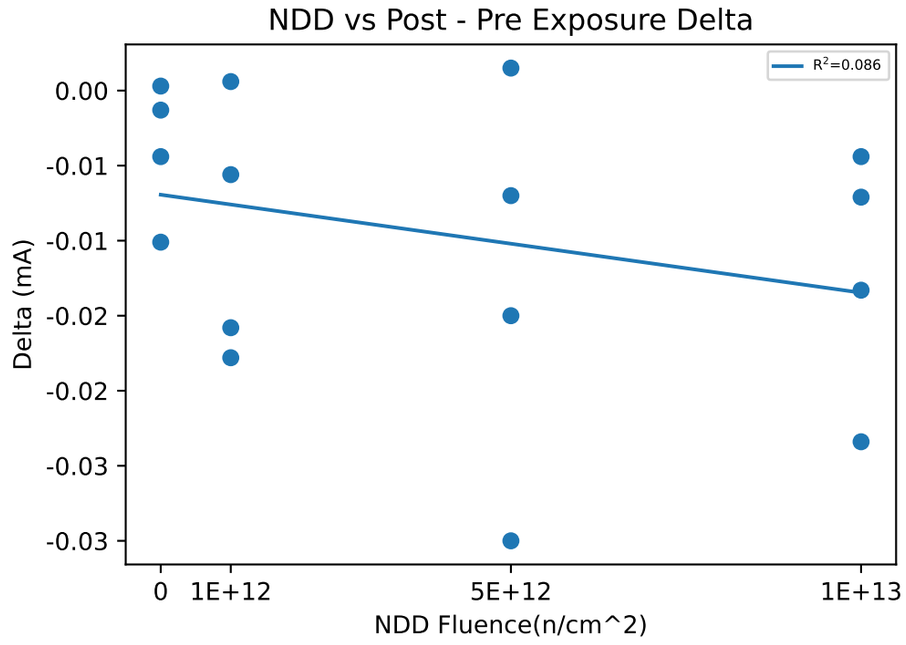
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.6873	3.6861	-0.0012
466	1e+12	NDD	3.6576	3.6553	-0.0023
762	0	CORRELATION	3.767	3.7609	-0.0061
769	1e+12	NDD	3.6308	3.6217	-0.0091
887	1e+12	NDD	3.6628	3.6527	-0.0101
891	0	CORRELATION	3.6875	3.6881	0.0006
927	1e+12	NDD	3.6571	3.6447	-0.0124
967	5e+12	NDD	3.6129	3.6152	0.0023
1204	1e+13	NDD	3.6604	3.6484	-0.012
1284	1e+13	NDD	3.6259	3.6045	-0.0214
1292	5e+12	NDD	3.683	3.6639	-0.0191
1364	1e+13	NDD	3.7148	3.7077	-0.0071
1383	5e+12	NDD	3.6429	3.6302	-0.0127
1388	5e+12	NDD	3.6051	3.6091	0.004
1427	1e+13	NDD	3.6979	3.6992	0.0013
1666	0	CORRELATION	3.6468	3.6457	-0.0011

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6468	3.6971	3.767	0.050346	3.6457	3.6952	3.7609	0.047958	-0.0061	-0.00195	0.0006	0.0028873
1e+12	3.6308	3.6521	3.6628	0.014416	3.6217	3.6436	3.6553	0.015281	-0.0124	-0.008475	-0.0023	0.0043423
5e+12	3.6051	3.636	3.683	0.035332	3.6091	3.6296	3.6639	0.024525	-0.0191	-0.006375	0.004	0.011326
1e+13	3.6259	3.6747	3.7148	0.039716	3.6045	3.665	3.7077	0.048058	-0.0214	-0.0098	0.0013	0.0094851

Device Test: 14.6 IDD|SUPPLY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_ACT_500K_NOLOAD





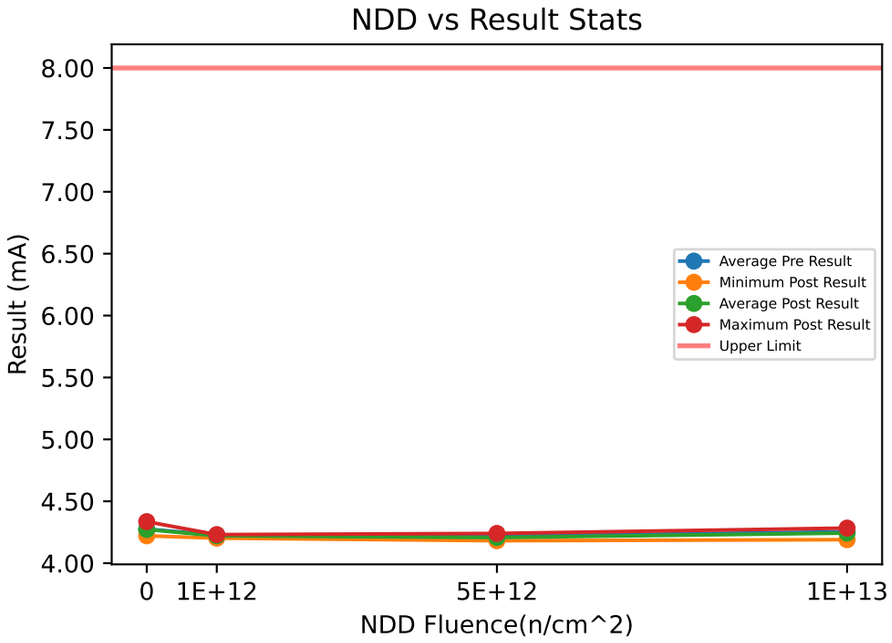
Test Results (Upper Limit = 17.0 (mA))

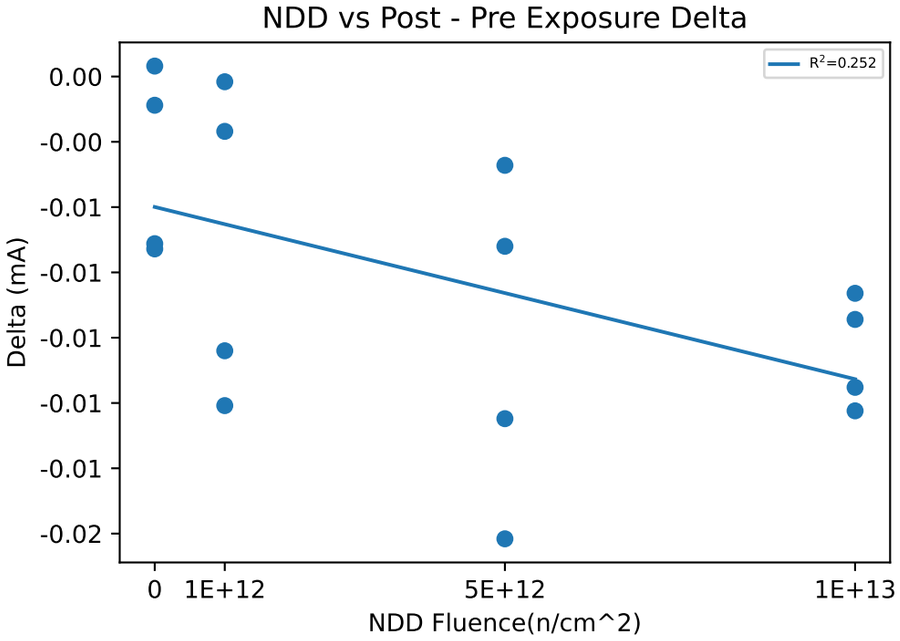
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	6.7436	6.7439	0.0003
466	1e+12	NDD	6.6909	6.6915	0.0006
762	0	CORRELATION	6.8989	6.8945	-0.0044
769	1e+12	NDD	6.6282	6.6226	-0.0056
887	1e+12	NDD	6.6643	6.6465	-0.0178
891	0	CORRELATION	6.784	6.7739	-0.0101
927	1e+12	NDD	6.6705	6.6547	-0.0158
967	5e+12	NDD	6.6175	6.6105	-0.007
1204	1e+13	NDD	6.654	6.6407	-0.0133
1284	1e+13	NDD	6.6138	6.5904	-0.0234
1292	5e+12	NDD	6.7527	6.7227	-0.03
1364	1e+13	NDD	6.7786	6.7715	-0.0071
1383	5e+12	NDD	6.651	6.636	-0.015
1388	5e+12	NDD	6.6483	6.6498	0.0015
1427	1e+13	NDD	6.794	6.7896	-0.0044
1666	0	CORRELATION	6.6918	6.6905	-0.0013

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.6918	6.7796	6.8989	0.088047	6.6905	6.7757	6.8945	0.086385	-0.0101	-0.003875	0.0003	0.0045858
1e+12	6.6282	6.6635	6.6909	0.026118	6.6226	6.6538	6.6915	0.028571	-0.0178	-0.00965	0.0006	0.0086739
5e+12	6.6175	6.6674	6.7527	0.058878	6.6105	6.6547	6.7227	0.048136	-0.03	-0.012625	0.0015	0.0134
1e+13	6.6138	6.7101	6.794	0.089726	6.5904	6.6981	6.7896	0.097731	-0.0234	-0.01205	-0.0044	0.0084343

Device Test: 14.7 IDD_DIS|STANDBY CURRENT/IN/4.5/4.5/0/0/4.5/500kHz//@IDD_DIS





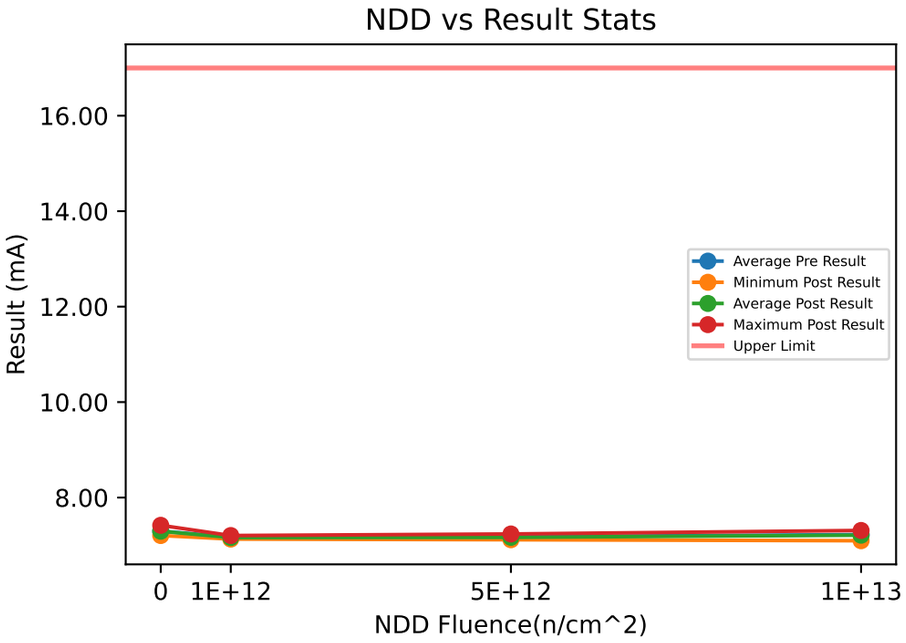
Test Results (Upper Limit = 8.0 (mA))

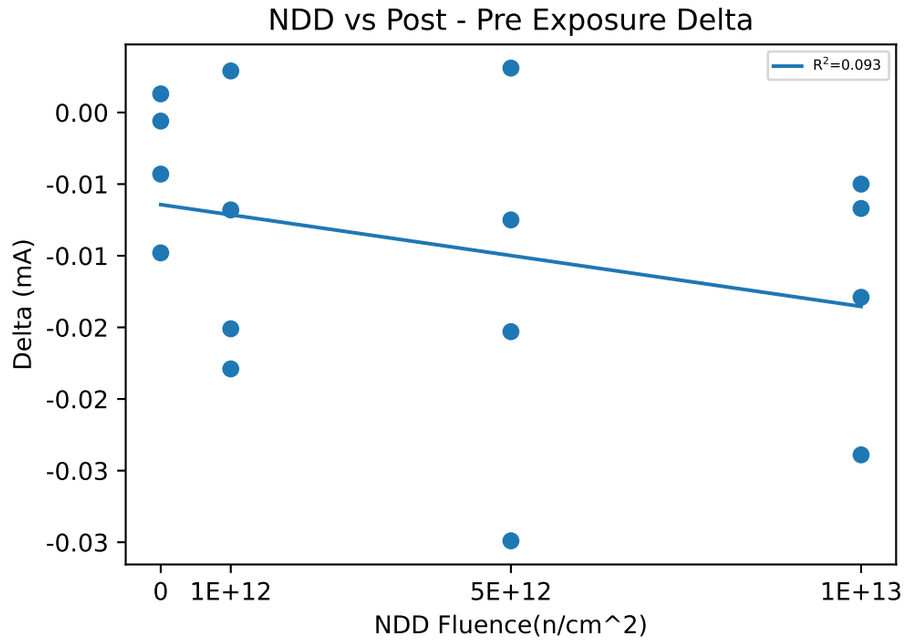
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.2666	4.2655	-0.0011
466	1e+12	NDD	4.2295	4.2293	-0.0002
762	0	CORRELATION	4.342	4.3356	-0.0064
769	1e+12	NDD	4.2043	4.2022	-0.0021
887	1e+12	NDD	4.2413	4.2308	-0.0105
891	0	CORRELATION	4.2731	4.2665	-0.0066
927	1e+12	NDD	4.2337	4.2211	-0.0126
967	5e+12	NDD	4.1979	4.1914	-0.0065
1204	1e+13	NDD	4.2355	4.2236	-0.0119
1284	1e+13	NDD	4.2026	4.1898	-0.0128
1292	5e+12	NDD	4.258	4.2403	-0.0177
1364	1e+13	NDD	4.2928	4.2835	-0.0093
1383	5e+12	NDD	4.2285	4.2154	-0.0131
1388	5e+12	NDD	4.1849	4.1815	-0.0034
1427	1e+13	NDD	4.2849	4.2766	-0.0083
1666	0	CORRELATION	4.2208	4.2212	0.0004

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.2208	4.2756	4.342	0.049997	4.2212	4.2722	4.3356	0.047251	-0.0066	-0.003425	0.0004	0.003604
1e+12	4.2043	4.2272	4.2413	0.016029	4.2022	4.2209	4.2308	0.013144	-0.0126	-0.00635	-0.0002	0.0061147
5e+12	4.1849	4.2173	4.258	0.032701	4.1815	4.2072	4.2403	0.026287	-0.0177	-0.010175	-0.0034	0.0064443
1e+13	4.2026	4.2539	4.2928	0.042601	4.1898	4.2434	4.2835	0.044629	-0.0128	-0.010575	-0.0083	0.0021219

Device Test: 14.8 IDD|SUPPLY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_ACT_500K_NOLOAD





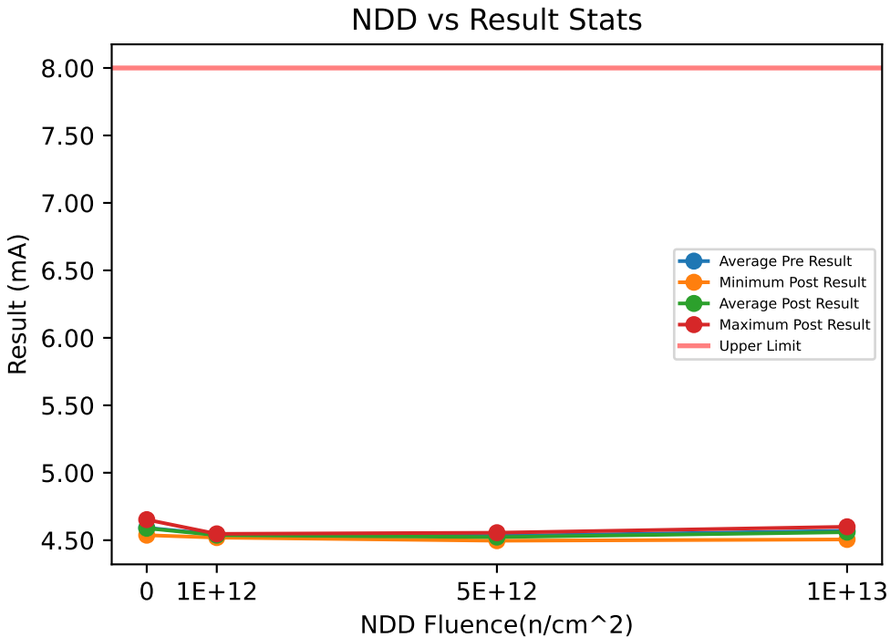
Test Results (Upper Limit = 17.0 (mA))

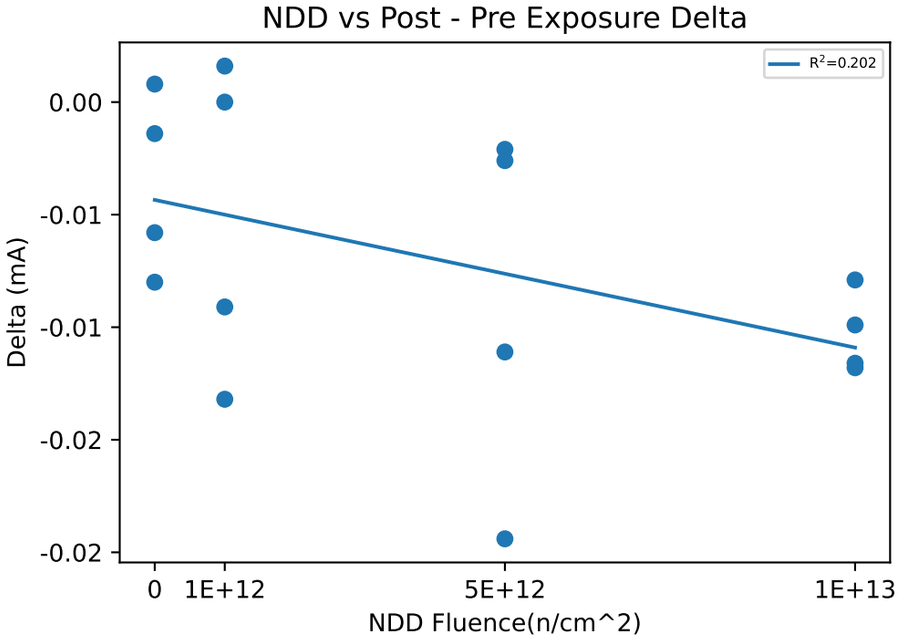
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.2594	7.2607	0.0013
466	1e+12	NDD	7.2014	7.2043	0.0029
762	0	CORRELATION	7.4231	7.4188	-0.0043
769	1e+12	NDD	7.1375	7.1307	-0.0068
887	1e+12	NDD	7.1705	7.1526	-0.0179
891	0	CORRELATION	7.3046	7.2948	-0.0098
927	1e+12	NDD	7.179	7.1639	-0.0151
967	5e+12	NDD	7.124	7.1165	-0.0075
1204	1e+13	NDD	7.1642	7.1513	-0.0129
1284	1e+13	NDD	7.1198	7.0959	-0.0239
1292	5e+12	NDD	7.267	7.2371	-0.0299
1364	1e+13	NDD	7.296	7.2893	-0.0067
1383	5e+12	NDD	7.161	7.1457	-0.0153
1388	5e+12	NDD	7.1636	7.1667	0.0031
1427	1e+13	NDD	7.3157	7.3107	-0.005
1666	0	CORRELATION	7.2054	7.2048	-0.0006

Test Statistics (mA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.2054	7.2981	7.4231	0.092661	7.2048	7.2948	7.4188	0.090625	-0.0098	-0.00335	0.0013	0.0048884
1e+12	7.1375	7.1721	7.2014	0.026494	7.1307	7.1629	7.2043	0.030865	-0.0179	-0.009225	0.0029	0.0093571
5e+12	7.124	7.1789	7.267	0.061455	7.1165	7.1665	7.2371	0.051371	-0.0299	-0.0124	0.0031	0.013891
1e+13	7.1198	7.2239	7.3157	0.096655	7.0959	7.2118	7.3107	0.10469	-0.0239	-0.012125	-0.005	0.0085527

Device Test: 14.9 IDD_DIS|STANDBY CURRENT/IN/5/5/0/0/5/500kHz//@IDD_DIS





Test Results (Upper Limit = 8.0 (mA))

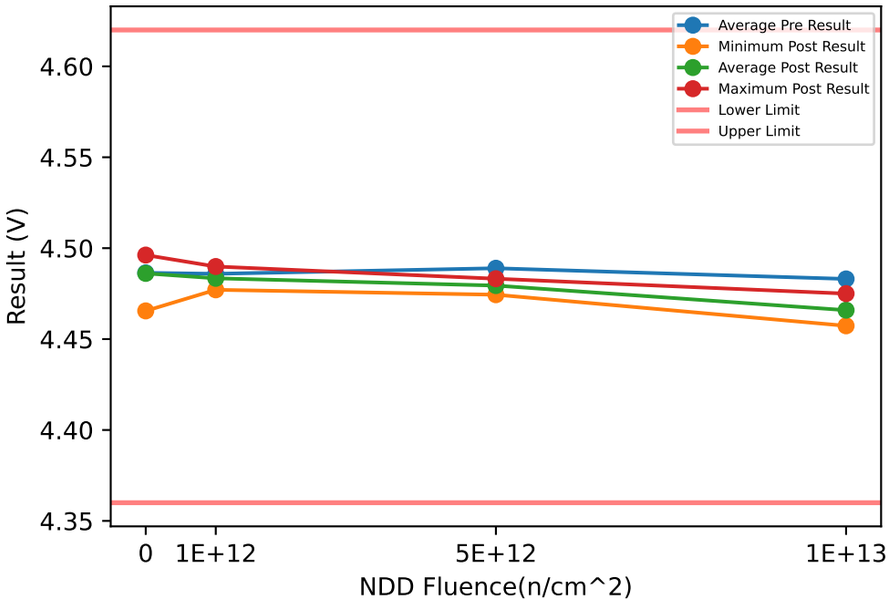
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.5815	4.5823	0.0008
466	1e+12	NDD	4.545	4.5466	0.0016
762	0	CORRELATION	4.6583	4.6525	-0.0058
769	1e+12	NDD	4.5194	4.5194	0
887	1e+12	NDD	4.5562	4.5471	-0.0091
891	0	CORRELATION	4.59	4.582	-0.008
927	1e+12	NDD	4.5498	4.5366	-0.0132
967	5e+12	NDD	4.5113	4.5092	-0.0021
1204	1e+13	NDD	4.5513	4.5395	-0.0118
1284	1e+13	NDD	4.5171	4.5055	-0.0116
1292	5e+12	NDD	4.5749	4.5555	-0.0194
1364	1e+13	NDD	4.6094	4.5995	-0.0099
1383	5e+12	NDD	4.5423	4.5312	-0.0111
1388	5e+12	NDD	4.4988	4.4962	-0.0026
1427	1e+13	NDD	4.6016	4.5937	-0.0079
1666	0	CORRELATION	4.5386	4.5372	-0.0014

Test Statistics (mA)

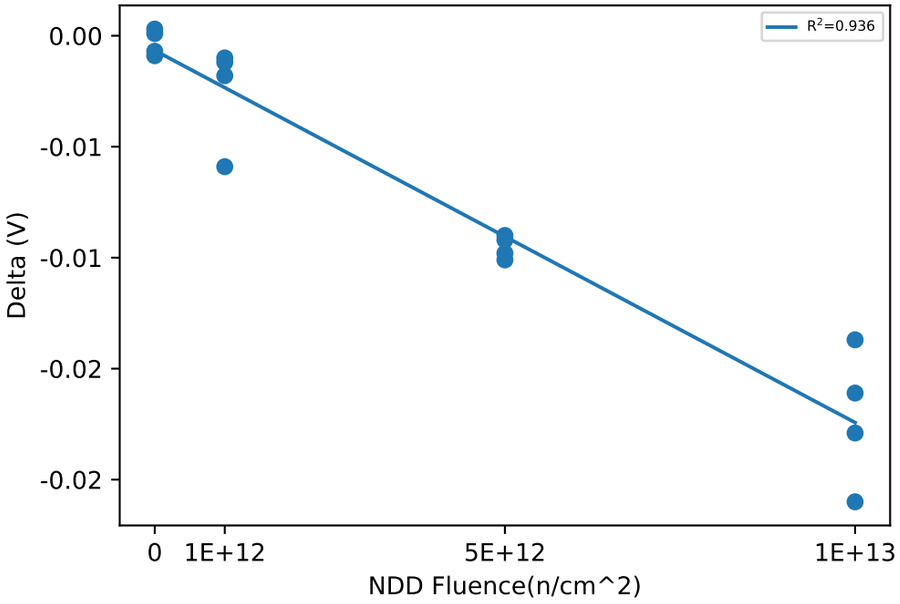
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.5386	4.5921	4.6583	0.049536	4.5372	4.5885	4.6525	0.047639	-0.008	-0.0036	0.0008	0.0040166
1e+12	4.5194	4.5426	4.5562	0.016133	4.5194	4.5374	4.5471	0.012953	-0.0132	-0.005175	0.0016	0.0071295
5e+12	4.4988	4.5318	4.5749	0.034045	4.4962	4.523	4.5555	0.026027	-0.0194	-0.0088	-0.0021	0.0081849
1e+13	4.5171	4.5699	4.6094	0.043585	4.5055	4.5595	4.5995	0.045039	-0.0118	-0.0103	-0.0079	0.0018129

Device Test: 15.1 VLDO|V_VLDO/VLDO/5/5/0/0/4.5/500kHz//@V_LDO_4P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

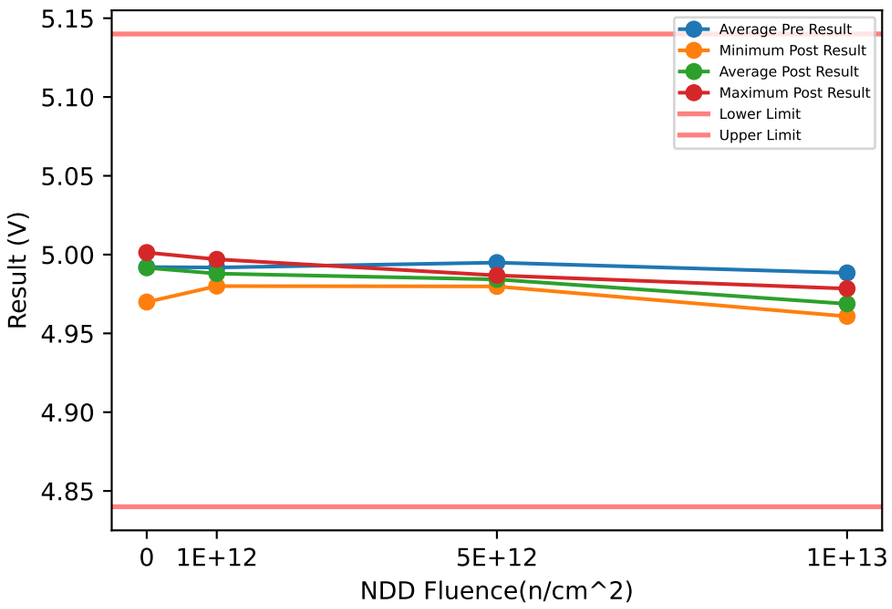
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.4664	4.4655	-0.0009
466	1e+12	NDD	4.4781	4.4771	-0.001
762	0	CORRELATION	4.4935	4.4936	0.0001
769	1e+12	NDD	4.4811	4.4793	-0.0018
887	1e+12	NDD	4.4886	4.4874	-0.0012
891	0	CORRELATION	4.4889	4.4892	0.0003
927	1e+12	NDD	4.4958	4.4899	-0.0059
967	5e+12	NDD	4.4933	4.4832	-0.0101
1204	1e+13	NDD	4.4864	4.4685	-0.0179
1284	1e+13	NDD	4.4911	4.475	-0.0161
1292	5e+12	NDD	4.4897	4.4807	-0.009
1364	1e+13	NDD	4.4783	4.4573	-0.021
1383	5e+12	NDD	4.4836	4.4744	-0.0092
1388	5e+12	NDD	4.4892	4.4794	-0.0098
1427	1e+13	NDD	4.4765	4.4628	-0.0137
1666	0	CORRELATION	4.4969	4.4962	-0.0007

Test Statistics (V)

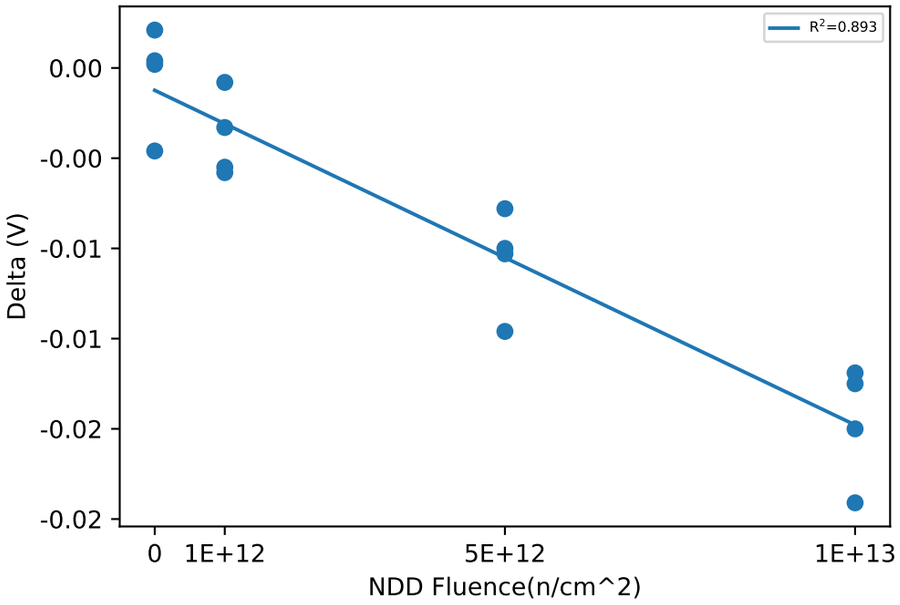
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4664	4.4864	4.4969	0.013747	4.4655	4.4861	4.4962	0.01405	-0.0009	-0.0003	0.0003	0.00058878
1e+12	4.4781	4.4859	4.4958	0.007941	4.4771	4.4834	4.4899	0.0061846	-0.0059	-0.002475	-0.001	0.0023085
5e+12	4.4836	4.4889	4.4933	0.0040071	4.4744	4.4794	4.4832	0.0037026	-0.0101	-0.009525	-0.009	0.00051235
1e+13	4.4765	4.4831	4.4911	0.0068675	4.4573	4.4659	4.475	0.0075969	-0.021	-0.017175	-0.0137	0.0030761

Device Test: 15.11 VLDO|V_VLDO/VLDO/12/12/0/0/5/500kHz//@V_LDO_5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

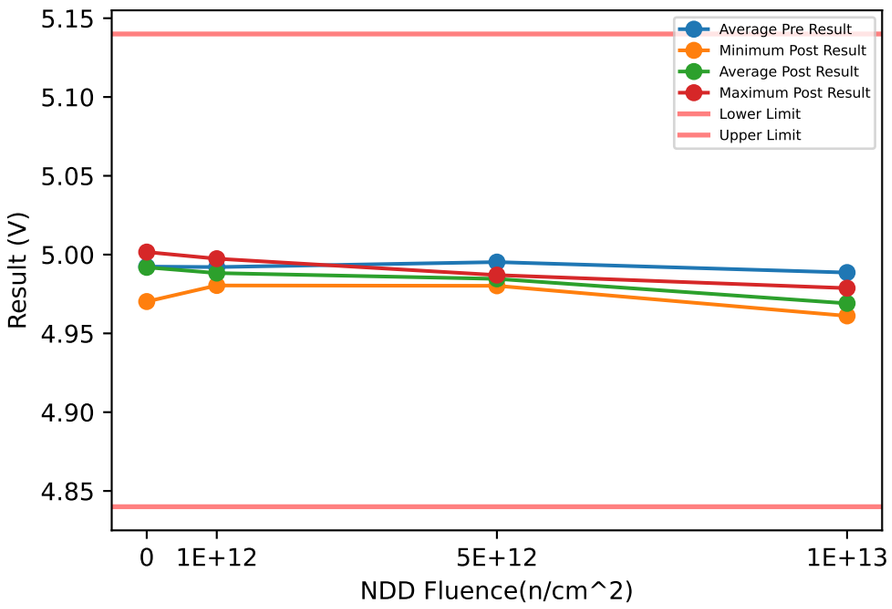
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.9678	4.9699	0.0021
466	1e+12	NDD	4.9808	4.98	-0.0008
762	0	CORRELATION	5.0011	5.0013	0.0002
769	1e+12	NDD	4.988	4.9825	-0.0055
887	1e+12	NDD	4.9956	4.9923	-0.0033
891	0	CORRELATION	4.9938	4.9942	0.0004
927	1e+12	NDD	5.0028	4.997	-0.0058
967	5e+12	NDD	5.0014	4.9868	-0.0146
1204	1e+13	NDD	4.9912	4.9712	-0.02
1284	1e+13	NDD	4.9953	4.9784	-0.0169
1292	5e+12	NDD	4.9949	4.9849	-0.01
1364	1e+13	NDD	4.9849	4.9608	-0.0241
1383	5e+12	NDD	4.9901	4.9798	-0.0103
1388	5e+12	NDD	4.9933	4.9855	-0.0078
1427	1e+13	NDD	4.9821	4.9646	-0.0175
1666	0	CORRELATION	5.0056	5.001	-0.0046

Test Statistics (V)

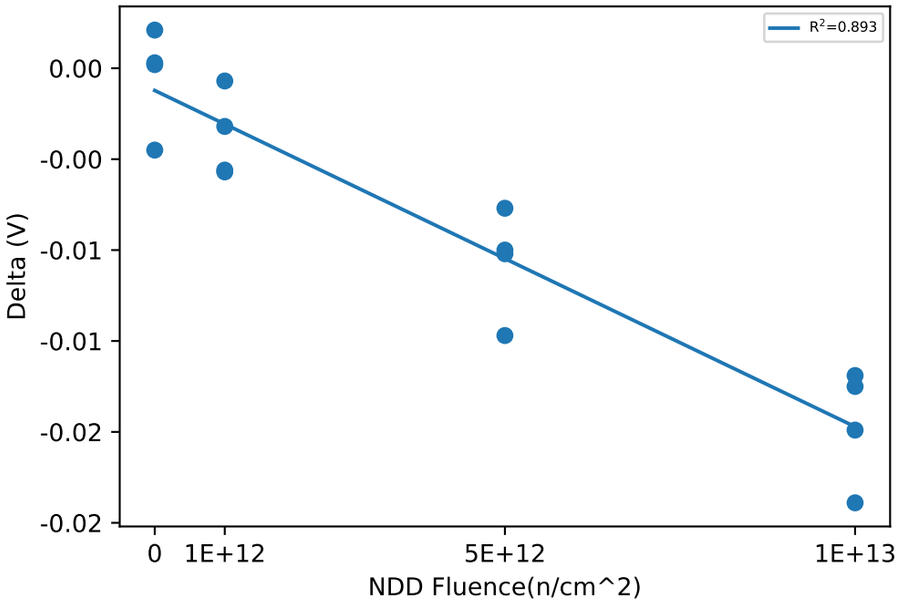
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9678	4.9921	5.0056	0.016898	4.9699	4.9916	5.0013	0.014834	-0.0046	-0.000475	0.0021	0.0028791
1e+12	4.9808	4.9918	5.0028	0.0095023	4.98	4.9879	4.997	0.008036	-0.0058	-0.00385	-0.0008	0.0023188
5e+12	4.9901	4.9949	5.0014	0.0047556	4.9798	4.9842	4.9868	0.0030708	-0.0146	-0.010675	-0.0078	0.0028441
1e+13	4.9821	4.9884	4.9953	0.005983	4.9608	4.9688	4.9784	0.0077363	-0.0241	-0.019625	-0.0169	0.0032715

Device Test: 15.12 VLDO|V_VLDO/VLDO/14/14/0/0/5/500kHz//@V_LDO_5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

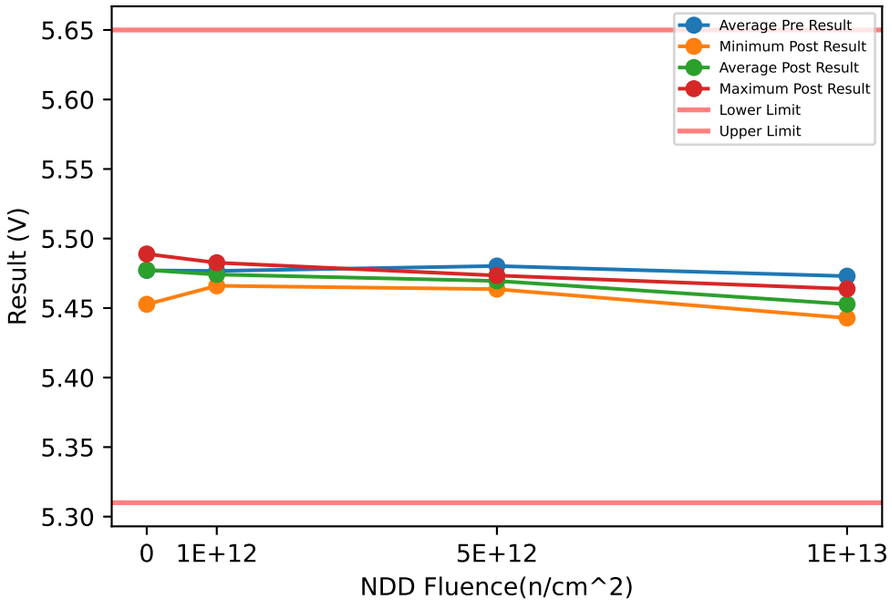
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.9681	4.9702	0.0021
466	1e+12	NDD	4.9811	4.9804	-0.0007
762	0	CORRELATION	5.0013	5.0016	0.0003
769	1e+12	NDD	4.9883	4.9827	-0.0056
887	1e+12	NDD	4.9958	4.9926	-0.0032
891	0	CORRELATION	4.9942	4.9944	0.0002
927	1e+12	NDD	5.0031	4.9974	-0.0057
967	5e+12	NDD	5.0017	4.987	-0.0147
1204	1e+13	NDD	4.9914	4.9715	-0.0199
1284	1e+13	NDD	4.9956	4.9787	-0.0169
1292	5e+12	NDD	4.9953	4.9853	-0.01
1364	1e+13	NDD	4.985	4.9611	-0.0239
1383	5e+12	NDD	4.9904	4.9802	-0.0102
1388	5e+12	NDD	4.9936	4.9859	-0.0077
1427	1e+13	NDD	4.9824	4.9649	-0.0175
1666	0	CORRELATION	5.0059	5.0014	-0.0045

Test Statistics (V)

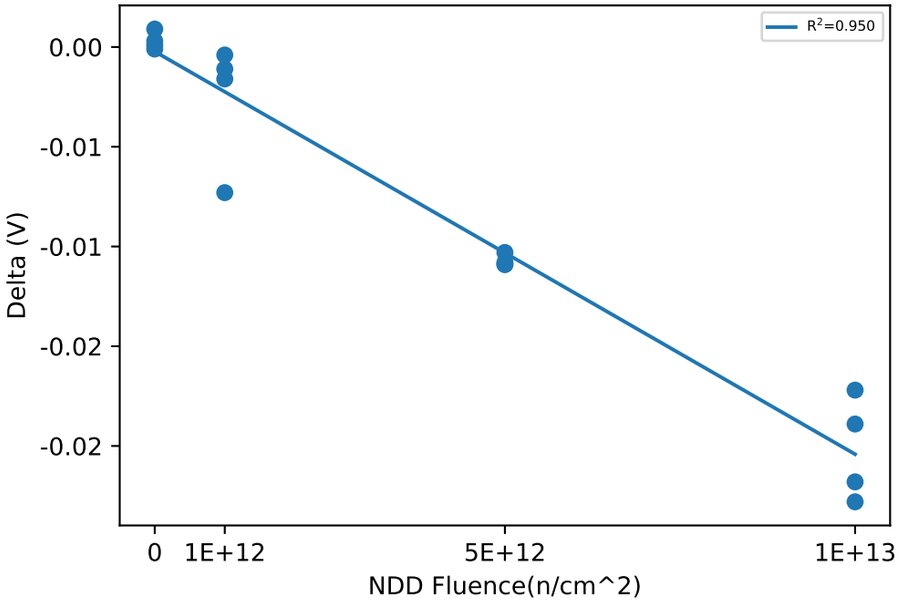
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9681	4.9924	5.0059	0.016884	4.9702	4.9919	5.0016	0.014849	-0.0045	-0.000475	0.0021	0.0028218
1e+12	4.9811	4.9921	5.0031	0.0094891	4.9804	4.9883	4.9974	0.0080637	-0.0057	-0.0038	-0.0007	0.0023678
5e+12	4.9904	4.9953	5.0017	0.0047557	4.9802	4.9846	4.987	0.0030166	-0.0147	-0.01065	-0.0077	0.0029286
1e+13	4.9824	4.9886	4.9956	0.0060067	4.9611	4.9691	4.9787	0.0077363	-0.0239	-0.01955	-0.0169	0.0031765

Device Test: 15.15 VLDO|V_VLDO/VLDO/6/6/0/0/5.5/500kHz//@V_LDO_5P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

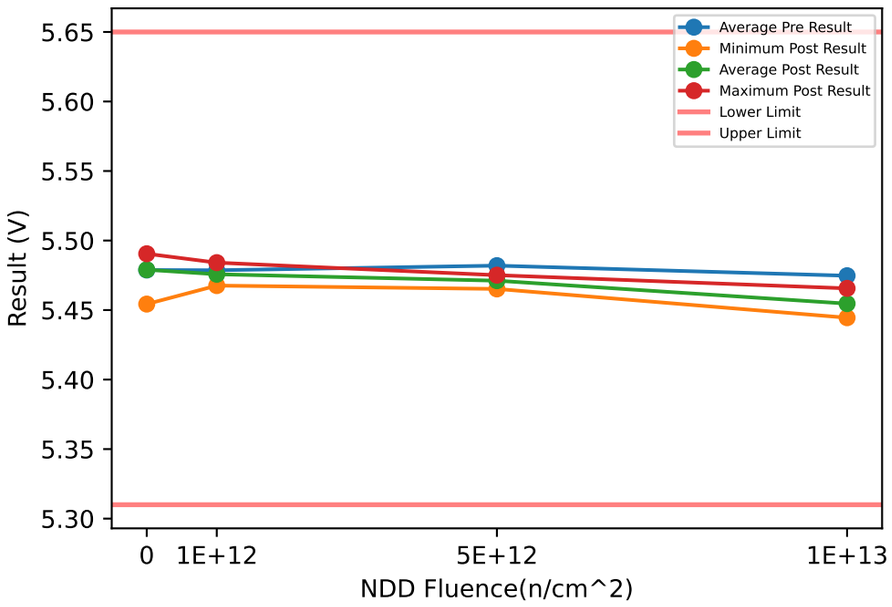
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.4528	5.4527	-0.0001
466	1e+12	NDD	5.4671	5.466	-0.0011
762	0	CORRELATION	5.4867	5.487	0.0003
769	1e+12	NDD	5.4692	5.4688	-0.0004
887	1e+12	NDD	5.4807	5.4791	-0.0016
891	0	CORRELATION	5.4808	5.4809	0.0001
927	1e+12	NDD	5.4899	5.4826	-0.0073
967	5e+12	NDD	5.4837	5.4734	-0.0103
1204	1e+13	NDD	5.4778	5.456	-0.0218
1284	1e+13	NDD	5.4827	5.4638	-0.0189
1292	5e+12	NDD	5.4821	5.4712	-0.0109
1364	1e+13	NDD	5.4656	5.4428	-0.0228
1383	5e+12	NDD	5.4745	5.4636	-0.0109
1388	5e+12	NDD	5.4807	5.4699	-0.0108
1427	1e+13	NDD	5.4657	5.4485	-0.0172
1666	0	CORRELATION	5.488	5.4889	0.0009

Test Statistics (V)

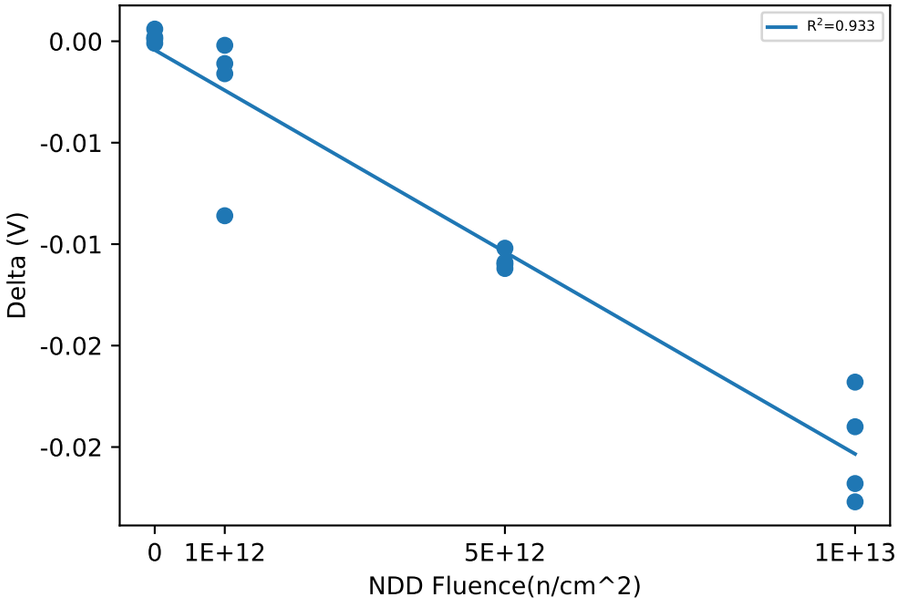
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4528	5.4771	5.488	0.016484	5.4527	5.4774	5.4889	0.0168	-0.0001	0.0003	0.0009	0.00043205
1e+12	5.4671	5.4767	5.4899	0.010625	5.466	5.4741	5.4826	0.007978	-0.0073	-0.0026	-0.0004	0.0031718
5e+12	5.4745	5.4802	5.4837	0.0040245	5.4636	5.4695	5.4734	0.0042058	-0.0109	-0.010725	-0.0103	0.00028723
1e+13	5.4656	5.4729	5.4827	0.0086635	5.4428	5.4528	5.4638	0.0091237	-0.0228	-0.020175	-0.0172	0.0025825

Device Test: 15.18 VLDO|V_VLDO/VLDO/12/12/0/0/5.5/500kHz//@V_LDO_5P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

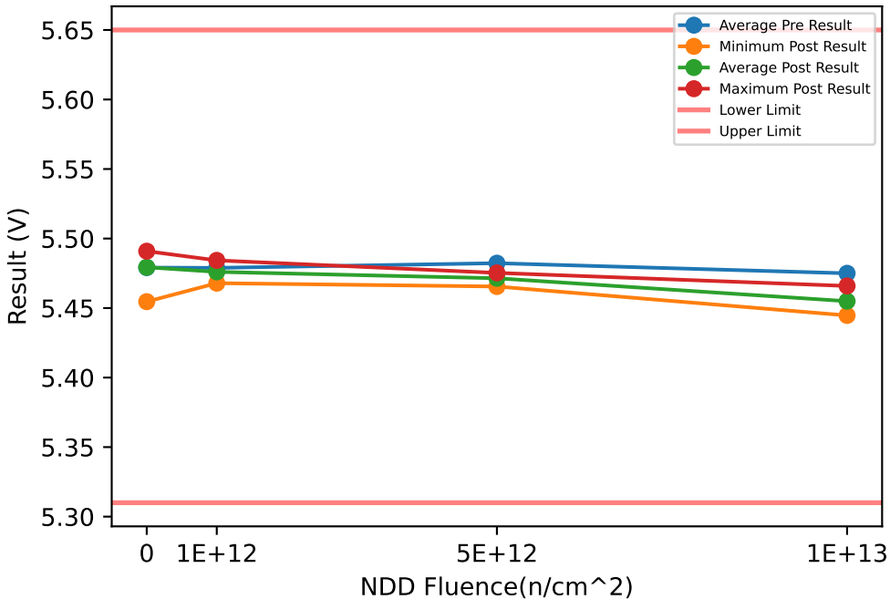
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.4544	5.4543	-0.0001
466	1e+12	NDD	5.4687	5.4676	-0.0011
762	0	CORRELATION	5.4884	5.4885	0.0001
769	1e+12	NDD	5.4707	5.4705	-0.0002
887	1e+12	NDD	5.4824	5.4808	-0.0016
891	0	CORRELATION	5.4825	5.4827	0.0002
927	1e+12	NDD	5.4927	5.4841	-0.0086
967	5e+12	NDD	5.4853	5.4751	-0.0102
1204	1e+13	NDD	5.4795	5.4577	-0.0218
1284	1e+13	NDD	5.4846	5.4656	-0.019
1292	5e+12	NDD	5.4838	5.4728	-0.011
1364	1e+13	NDD	5.4672	5.4445	-0.0227
1383	5e+12	NDD	5.4761	5.4652	-0.0109
1388	5e+12	NDD	5.4826	5.4714	-0.0112
1427	1e+13	NDD	5.4675	5.4507	-0.0168
1666	0	CORRELATION	5.4899	5.4905	0.0006

Test Statistics (V)

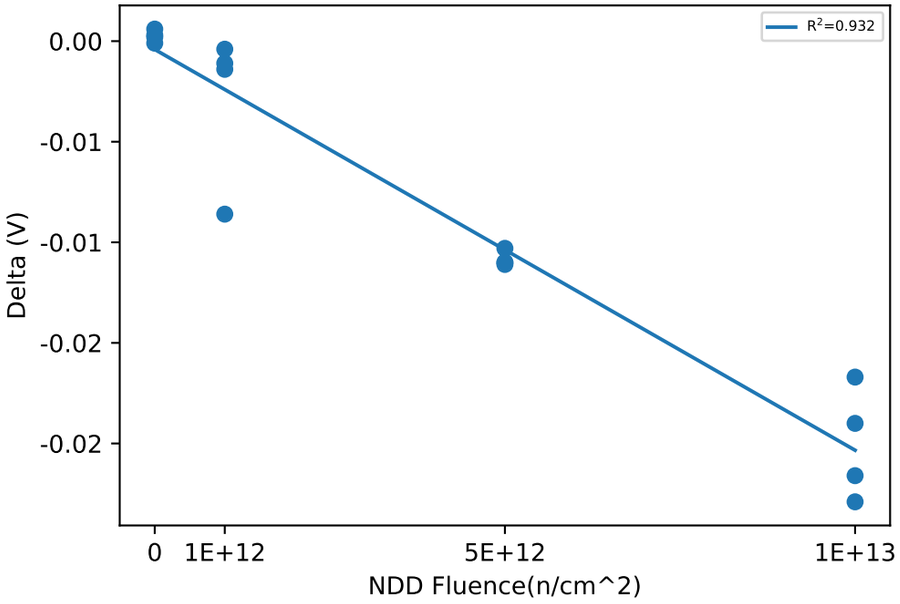
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4544	5.4788	5.4899	0.016577	5.4543	5.479	5.4905	0.016796	-0.0001	0.0002	0.0006	0.00029439
1e+12	5.4687	5.4786	5.4927	0.01116	5.4676	5.4757	5.4841	0.0079417	-0.0086	-0.002875	-0.0002	0.0038604
5e+12	5.4761	5.4819	5.4853	0.0040534	5.4652	5.4711	5.4751	0.0042343	-0.0112	-0.010825	-0.0102	0.00043493
1e+13	5.4672	5.4747	5.4846	0.0087396	5.4445	5.4546	5.4656	0.009089	-0.0227	-0.020075	-0.0168	0.0026924

Device Test: 15.19 VLDO|V_VLDO/VLDO/14/14/0/0/5.5/500kHz//@V_LDO_5P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 5.31, Upper Limit = 5.65 (V))

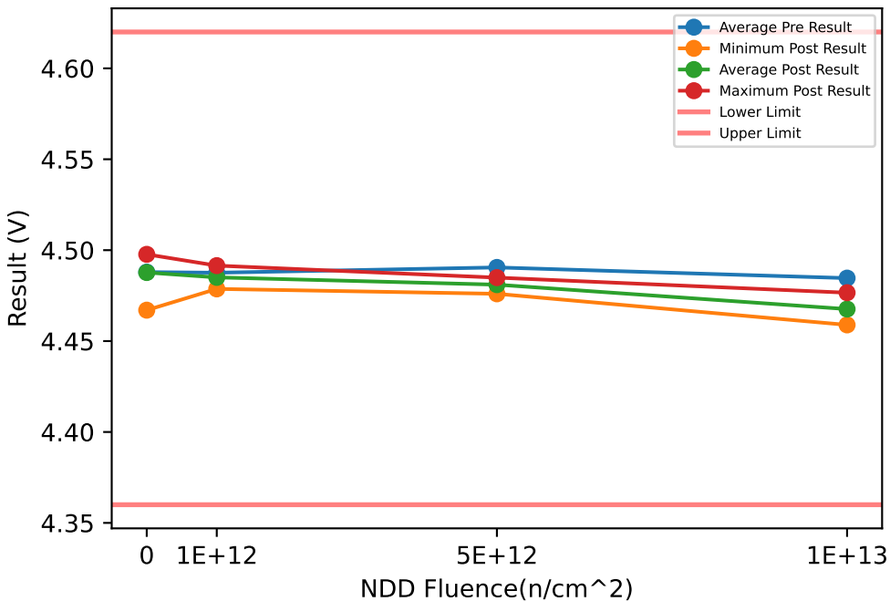
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.4547	5.4546	-0.0001
466	1e+12	NDD	5.469	5.4679	-0.0011
762	0	CORRELATION	5.4886	5.4889	0.0003
769	1e+12	NDD	5.4711	5.4707	-0.0004
887	1e+12	NDD	5.4826	5.4812	-0.0014
891	0	CORRELATION	5.4828	5.483	0.0002
927	1e+12	NDD	5.4929	5.4843	-0.0086
967	5e+12	NDD	5.4856	5.4753	-0.0103
1204	1e+13	NDD	5.4797	5.4581	-0.0216
1284	1e+13	NDD	5.4849	5.4659	-0.019
1292	5e+12	NDD	5.4841	5.4731	-0.011
1364	1e+13	NDD	5.4676	5.4447	-0.0229
1383	5e+12	NDD	5.4766	5.4655	-0.0111
1388	5e+12	NDD	5.4828	5.4718	-0.011
1427	1e+13	NDD	5.4678	5.4511	-0.0167
1666	0	CORRELATION	5.4903	5.4909	0.0006

Test Statistics (V)

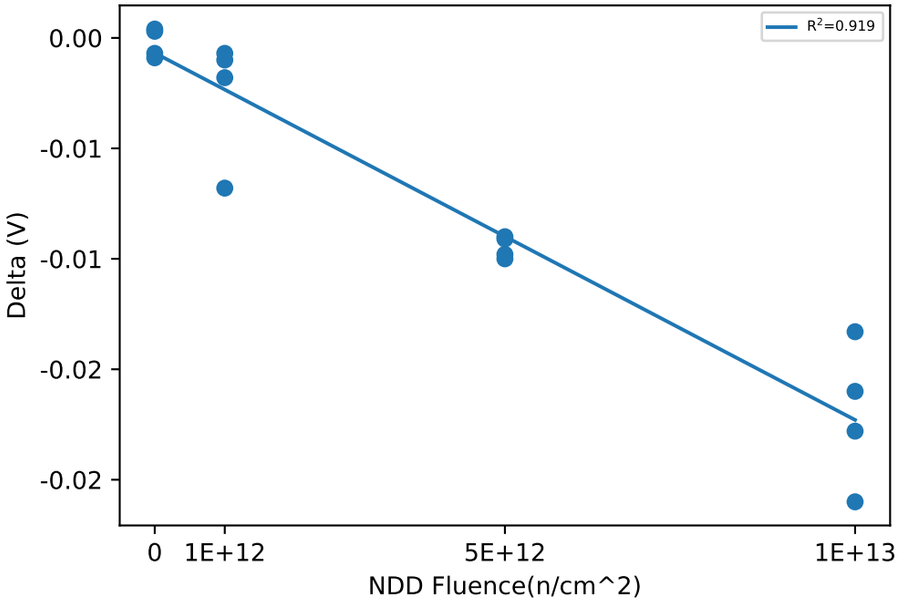
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.4547	5.4791	5.4903	0.016581	5.4546	5.4794	5.4909	0.016837	-0.0001	0.00025	0.0006	0.00028868
1e+12	5.469	5.4789	5.4929	0.011084	5.4679	5.476	5.4843	0.0079504	-0.0086	-0.002875	-0.0004	0.0038396
5e+12	5.4766	5.4823	5.4856	0.0039525	5.4655	5.4714	5.4753	0.0042058	-0.0111	-0.01085	-0.0103	0.00036968
1e+13	5.4676	5.475	5.4849	0.0086929	5.4447	5.455	5.4659	0.0091234	-0.0229	-0.02005	-0.0167	0.0027598

Device Test: 15.4 VLDO|V_VLDO/VLDO/12/12/0/0/4.5/500kHz//@V_LDO_4P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

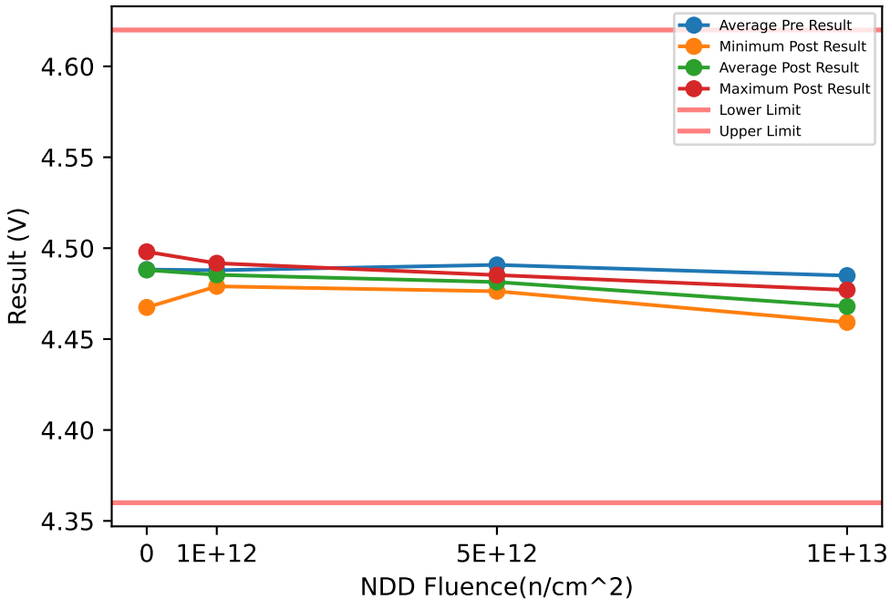
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.4677	4.467	-0.0007
466	1e+12	NDD	4.4794	4.4787	-0.0007
762	0	CORRELATION	4.4949	4.4952	0.0003
769	1e+12	NDD	4.4827	4.4809	-0.0018
887	1e+12	NDD	4.49	4.489	-0.001
891	0	CORRELATION	4.4905	4.4909	0.0004
927	1e+12	NDD	4.4983	4.4915	-0.0068
967	5e+12	NDD	4.4949	4.4849	-0.01
1204	1e+13	NDD	4.488	4.4702	-0.0178
1284	1e+13	NDD	4.4926	4.4766	-0.016
1292	5e+12	NDD	4.4914	4.4823	-0.0091
1364	1e+13	NDD	4.4799	4.4589	-0.021
1383	5e+12	NDD	4.485	4.476	-0.009
1388	5e+12	NDD	4.4907	4.4809	-0.0098
1427	1e+13	NDD	4.478	4.4647	-0.0133
1666	0	CORRELATION	4.4986	4.4977	-0.0009

Test Statistics (V)

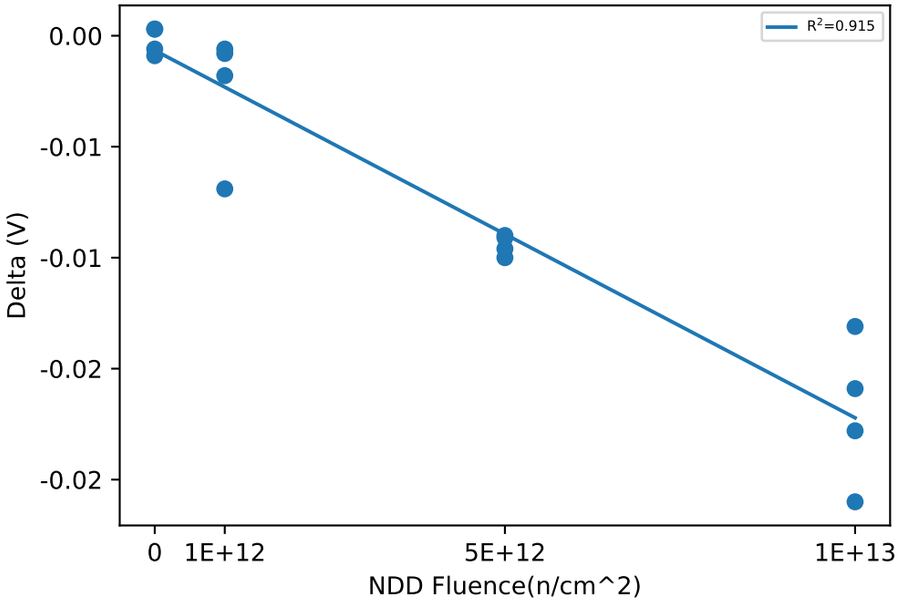
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4677	4.4879	4.4986	0.013884	4.467	4.4877	4.4977	0.014083	-0.0009	-0.000225	0.0004	0.0006702
1e+12	4.4794	4.4876	4.4983	0.0083964	4.4787	4.485	4.4915	0.0061846	-0.0068	-0.002575	-0.0007	0.0028547
5e+12	4.485	4.4905	4.4949	0.0041012	4.476	4.481	4.4849	0.0037375	-0.01	-0.009475	-0.009	0.00049917
1e+13	4.478	4.4846	4.4926	0.0068607	4.4589	4.4676	4.4766	0.0075688	-0.021	-0.017025	-0.0133	0.0032315

Device Test: 15.5 VLDO|V_VLDO/VLDO/14/14/0/0/4.5/500kHz//@V_LDO_4P5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 4.36, Upper Limit = 4.62 (V))

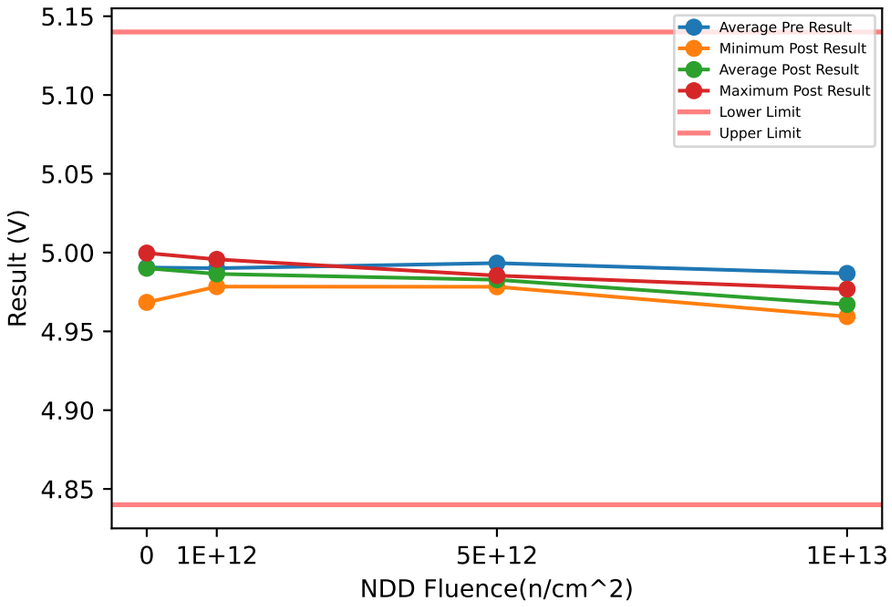
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.468	4.4674	-0.0006
466	1e+12	NDD	4.4796	4.479	-0.0006
762	0	CORRELATION	4.4952	4.4955	0.0003
769	1e+12	NDD	4.483	4.4812	-0.0018
887	1e+12	NDD	4.4902	4.4894	-0.0008
891	0	CORRELATION	4.4908	4.4911	0.0003
927	1e+12	NDD	4.4986	4.4917	-0.0069
967	5e+12	NDD	4.4952	4.4852	-0.01
1204	1e+13	NDD	4.4883	4.4705	-0.0178
1284	1e+13	NDD	4.4929	4.477	-0.0159
1292	5e+12	NDD	4.4917	4.4827	-0.009
1364	1e+13	NDD	4.4802	4.4592	-0.021
1383	5e+12	NDD	4.4854	4.4763	-0.0091
1388	5e+12	NDD	4.4909	4.4813	-0.0096
1427	1e+13	NDD	4.4782	4.4651	-0.0131
1666	0	CORRELATION	4.4989	4.498	-0.0009

Test Statistics (V)

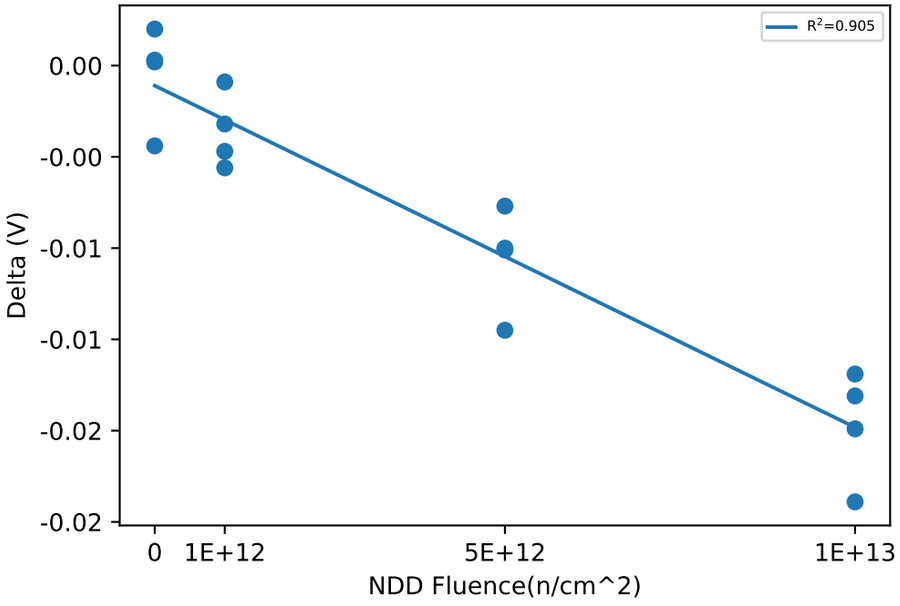
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.468	4.4882	4.4989	0.013884	4.4674	4.488	4.498	0.014026	-0.0009	-0.000225	0.0003	0.00061847
1e+12	4.4796	4.4878	4.4986	0.0084196	4.479	4.4853	4.4917	0.0061716	-0.0069	-0.002525	-0.0006	0.0029635
5e+12	4.4854	4.4908	4.4952	0.0040554	4.4763	4.4814	4.4852	0.0037482	-0.01	-0.009425	-0.009	0.00046458
1e+13	4.4782	4.4849	4.4929	0.006893	4.4592	4.468	4.477	0.0075958	-0.021	-0.01695	-0.0131	0.0033191

Device Test: 15.8 VLDO|V_VLDO/VLDO/5.5/5.5/0/0/5/500kHz//@V_LDO_5

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



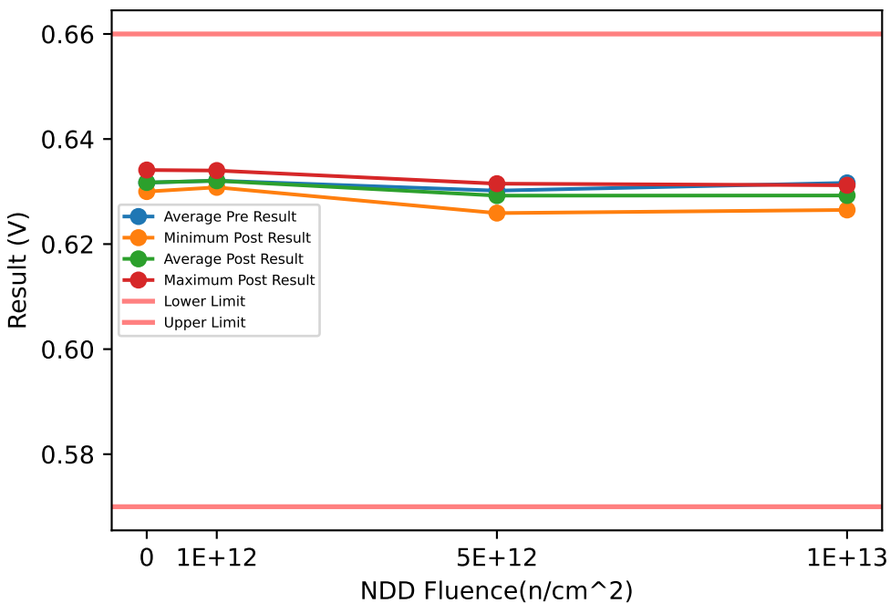
Test Results (Lower Limit = 4.84, Upper Limit = 5.14 (V))

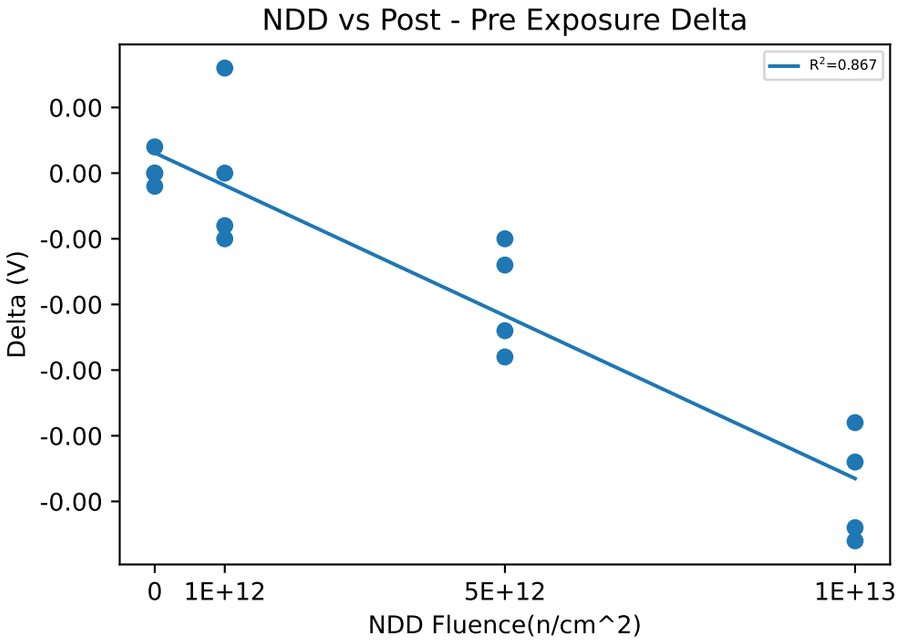
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.9664	4.9684	0.002
466	1e+12	NDD	4.9793	4.9784	-0.0009
762	0	CORRELATION	4.9995	4.9997	0.0002
769	1e+12	NDD	4.9866	4.981	-0.0056
887	1e+12	NDD	4.994	4.9908	-0.0032
891	0	CORRELATION	4.9923	4.9926	0.0003
927	1e+12	NDD	5.0004	4.9957	-0.0047
967	5e+12	NDD	4.9999	4.9854	-0.0145
1204	1e+13	NDD	4.9895	4.9696	-0.0199
1284	1e+13	NDD	4.9937	4.9768	-0.0169
1292	5e+12	NDD	4.9933	4.9833	-0.01
1364	1e+13	NDD	4.9833	4.9594	-0.0239
1383	5e+12	NDD	4.9884	4.9783	-0.0101
1388	5e+12	NDD	4.9917	4.984	-0.0077
1427	1e+13	NDD	4.9806	4.9625	-0.0181
1666	0	CORRELATION	5.0039	4.9995	-0.0044

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.9664	4.9905	5.0039	0.016779	4.9684	4.9901	4.9997	0.014806	-0.0044	-0.000475	0.002	0.0027439
1e+12	4.9793	4.9901	5.0004	0.0091321	4.9784	4.9865	4.9957	0.0081443	-0.0056	-0.0036	-0.0009	0.0020543
5e+12	4.9884	4.9933	4.9999	0.0048349	4.9783	4.9828	4.9854	0.0030925	-0.0145	-0.010575	-0.0077	0.0028418
1e+13	4.9806	4.9868	4.9937	0.0059326	4.9594	4.9671	4.9768	0.0077629	-0.0239	-0.0197	-0.0169	0.0030594

Device Test: 16.1 LEVEL|EN_RISE/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_RISE





Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

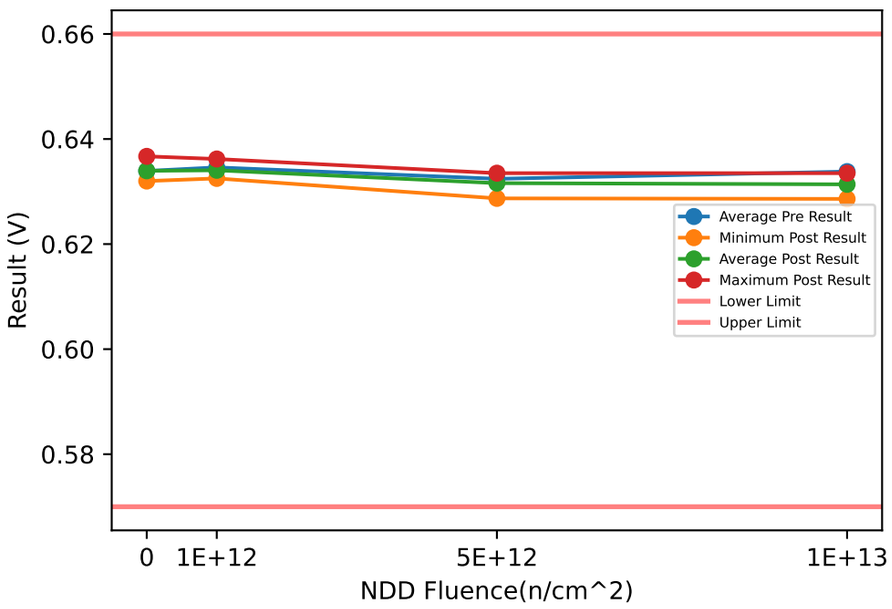
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6306	0.6306	0
466	1e+12	NDD	0.6313	0.6308	-0.0005
762	0	CORRELATION	0.632	0.6322	0.0002
769	1e+12	NDD	0.6318	0.6314	-0.0004
887	1e+12	NDD	0.634	0.634	0
891	0	CORRELATION	0.6342	0.6341	-0.0001
927	1e+12	NDD	0.6312	0.632	0.0008
967	5e+12	NDD	0.6273	0.6259	-0.0014
1204	1e+13	NDD	0.6292	0.6265	-0.0027
1284	1e+13	NDD	0.6319	0.63	-0.0019
1292	5e+12	NDD	0.6301	0.6294	-0.0007
1364	1e+13	NDD	0.6321	0.6293	-0.0028
1383	5e+12	NDD	0.632	0.6315	-0.0005
1388	5e+12	NDD	0.6313	0.6301	-0.0012
1427	1e+13	NDD	0.6334	0.6312	-0.0022
1666	0	CORRELATION	0.63	0.63	0

Test Statistics (V)

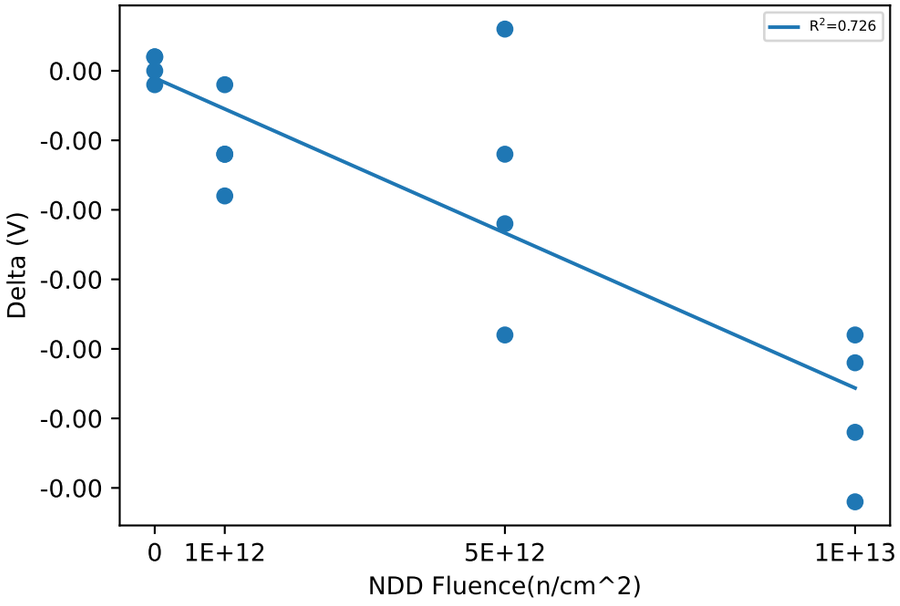
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.63	0.6317	0.6342	0.0018655	0.63	0.63172	0.6341	0.0018355	-0.0001	2.5e-05	0.0002	0.00012583
1e+12	0.6312	0.63207	0.634	0.0013099	0.6308	0.63205	0.634	0.0013892	-0.0005	-2.5e-05	0.0008	0.0005909
5e+12	0.6273	0.63017	0.632	0.002071	0.6259	0.62922	0.6315	0.0023824	-0.0014	-0.00095	-0.0005	0.00042032
1e+13	0.6292	0.63165	0.6334	0.0017635	0.6265	0.62925	0.6312	0.0019942	-0.0028	-0.0024	-0.0019	0.00042426

Device Test: 16.10 LEVEL|EN_RISE/EN/14/14/0/0/5/500kHz//@V_EN_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

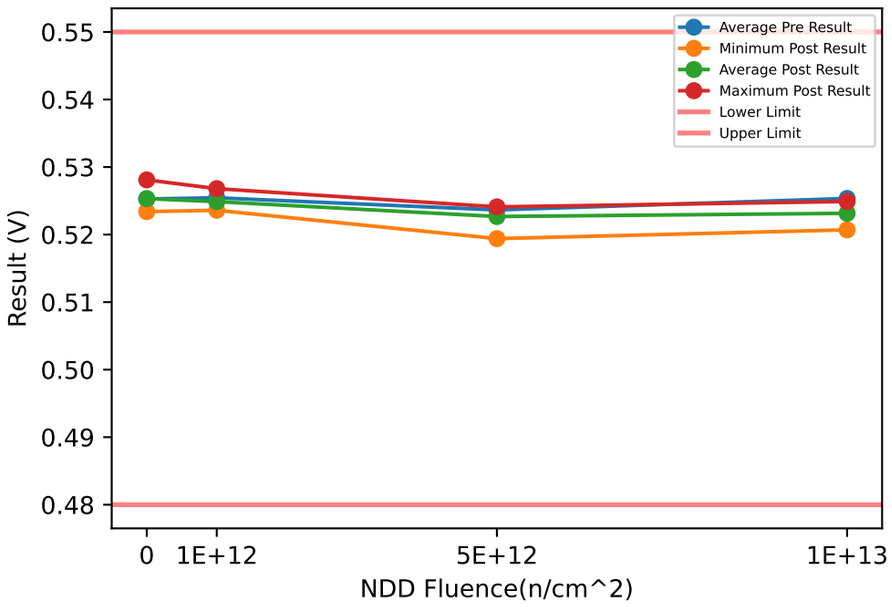
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6328	0.6329	0.0001
466	1e+12	NDD	0.6334	0.6325	-0.0009
762	0	CORRELATION	0.6341	0.6342	0.0001
769	1e+12	NDD	0.6341	0.634	-0.0001
887	1e+12	NDD	0.6368	0.6362	-0.0006
891	0	CORRELATION	0.6368	0.6367	-0.0001
927	1e+12	NDD	0.6341	0.6335	-0.0006
967	5e+12	NDD	0.6298	0.6287	-0.0011
1204	1e+13	NDD	0.6312	0.6286	-0.0026
1284	1e+13	NDD	0.634	0.6319	-0.0021
1292	5e+12	NDD	0.6318	0.6321	0.0003
1364	1e+13	NDD	0.6346	0.6315	-0.0031
1383	5e+12	NDD	0.6341	0.6335	-0.0006
1388	5e+12	NDD	0.634	0.6321	-0.0019
1427	1e+13	NDD	0.6354	0.6335	-0.0019
1666	0	CORRELATION	0.632	0.632	0

Test Statistics (V)

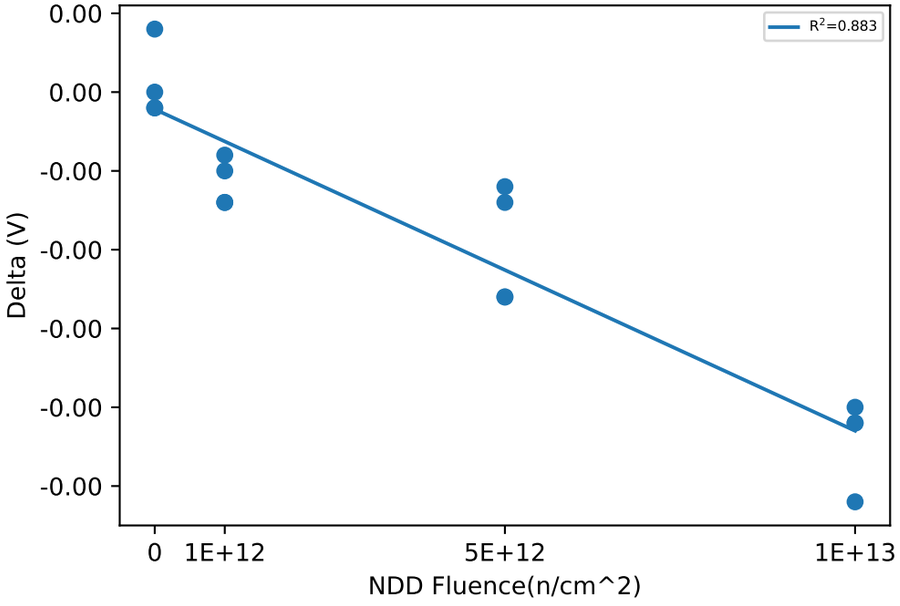
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.632	0.63393	0.6368	0.002103	0.632	0.63395	0.6367	0.0020437	-0.0001	2.5e-05	0.0001	9.5743e-05
1e+12	0.6334	0.6346	0.6368	0.0015033	0.6325	0.63405	0.6362	0.0015631	-0.0009	-0.00055	-0.0001	0.00033166
5e+12	0.6298	0.63243	0.6341	0.0020467	0.6287	0.6316	0.6335	0.0020429	-0.0019	-0.000825	0.0003	0.0009215
1e+13	0.6312	0.6338	0.6354	0.0018257	0.6286	0.63138	0.6335	0.0020419	-0.0031	-0.002425	-0.0019	0.00053774

Device Test: 16.11 LEVEL|EN_FALL/EN/14/14/0/0/5/500kHz//@V_EN_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

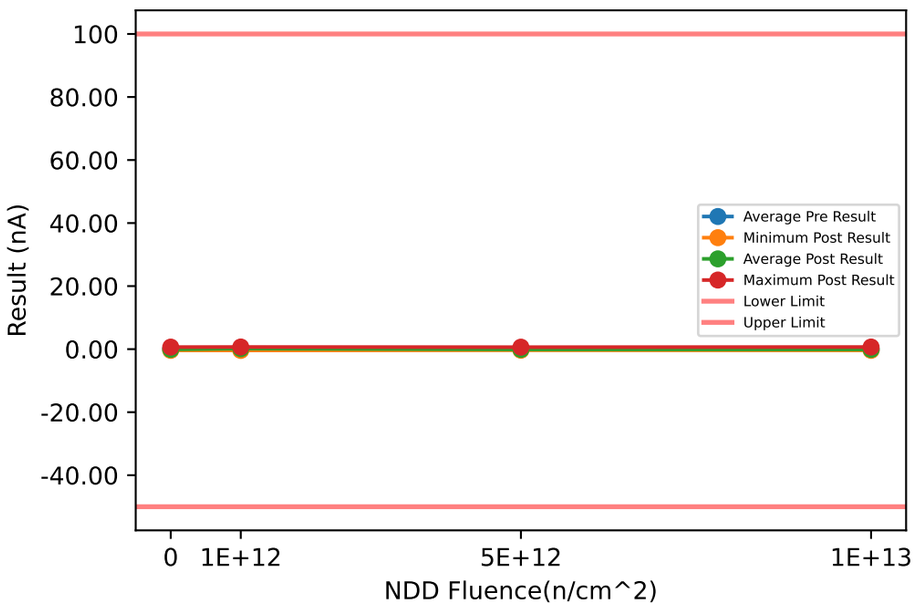
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5235	0.5235	0
466	1e+12	NDD	0.524	0.5236	-0.0004
762	0	CORRELATION	0.5264	0.5263	-0.0001
769	1e+12	NDD	0.5255	0.5248	-0.0007
887	1e+12	NDD	0.5275	0.5268	-0.0007
891	0	CORRELATION	0.5277	0.5281	0.0004
927	1e+12	NDD	0.5248	0.5243	-0.0005
967	5e+12	NDD	0.5207	0.5194	-0.0013
1204	1e+13	NDD	0.5228	0.5207	-0.0021
1284	1e+13	NDD	0.5254	0.5234	-0.002
1292	5e+12	NDD	0.5242	0.5236	-0.0006
1364	1e+13	NDD	0.5262	0.5236	-0.0026
1383	5e+12	NDD	0.5248	0.5241	-0.0007
1388	5e+12	NDD	0.5249	0.5236	-0.0013
1427	1e+13	NDD	0.527	0.5249	-0.0021
1666	0	CORRELATION	0.5235	0.5234	-0.0001

Test Statistics (V)

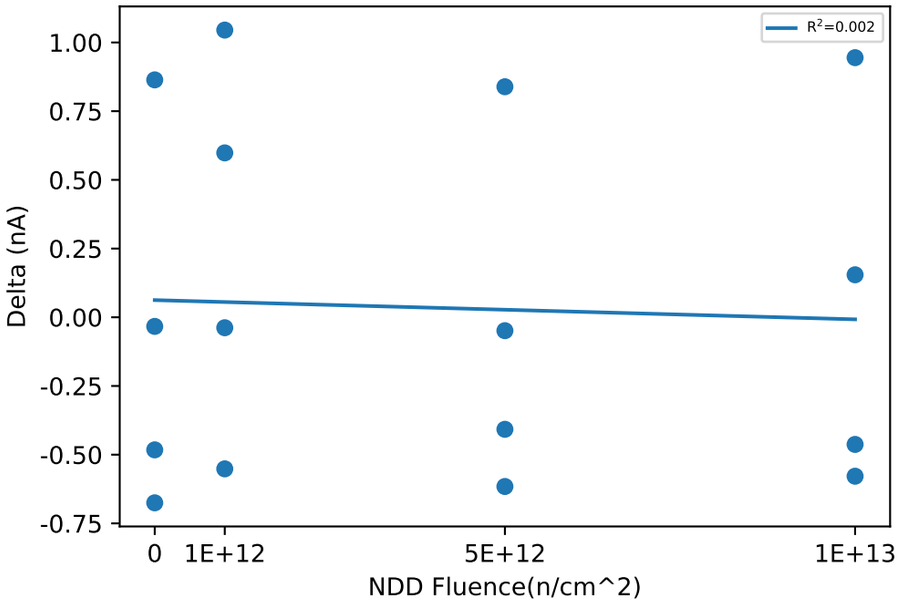
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5235	0.52527	0.5277	0.0021172	0.5234	0.52533	0.5281	0.0022867	-0.0001	5e-05	0.0004	0.00023805
1e+12	0.524	0.52545	0.5275	0.0014978	0.5236	0.52487	0.5268	0.0013745	-0.0007	-0.000575	-0.0004	0.00015
5e+12	0.5207	0.52365	0.5249	0.0019908	0.5194	0.52268	0.5241	0.002196	-0.0013	-0.000975	-0.0006	0.00037749
1e+13	0.5228	0.52535	0.527	0.0018212	0.5207	0.52315	0.5249	0.0017635	-0.0026	-0.0022	-0.002	0.0002708

Device Test: 16.15 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK_1V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = -50.0, Upper Limit = 100.0 (nA))

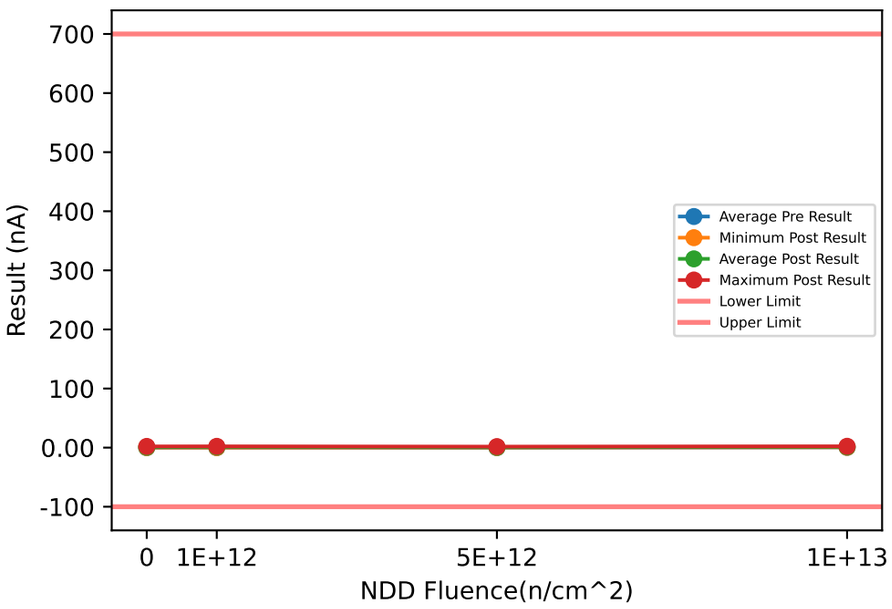
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.1538	-0.3287	-0.4825
466	1e+12	NDD	0.079	0.6772	0.5982
762	0	CORRELATION	-0.2238	-0.257	-0.0332
769	1e+12	NDD	-0.3772	0.6679	1.0451
887	1e+12	NDD	-0.3674	-0.4055	-0.0381
891	0	CORRELATION	0.2884	-0.3868	-0.6752
927	1e+12	NDD	0.2572	-0.2944	-0.5516
967	5e+12	NDD	-0.2115	0.6274	0.8389
1204	1e+13	NDD	0.2166	-0.3618	-0.5784
1284	1e+13	NDD	0.079	-0.3837	-0.4627
1292	5e+12	NDD	0.2665	-0.3493	-0.6158
1364	1e+13	NDD	-0.4303	-0.2757	0.1546
1383	5e+12	NDD	-0.2737	-0.3225	-0.0488
1388	5e+12	NDD	0.0883	-0.3194	-0.4077
1427	1e+13	NDD	-0.2737	0.671	0.9447
1666	0	CORRELATION	-0.2178	0.6461	0.8639

Test Statistics (nA)

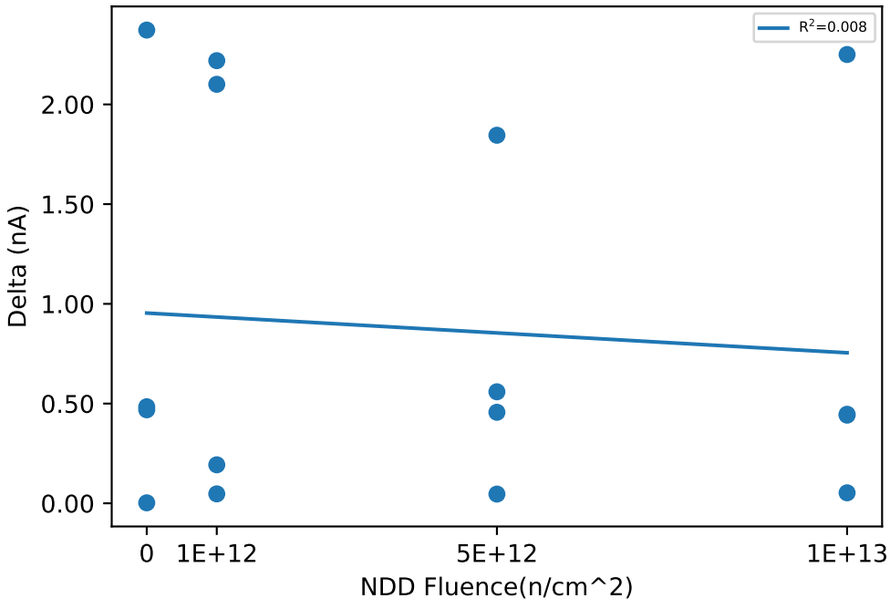
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2238	0.00015	0.2884	0.26099	-0.3868	-0.0816	0.6461	0.48803	-0.6752	-0.08175	0.8639	0.68542
1e+12	-0.3772	-0.1021	0.2572	0.32039	-0.4055	0.1613	0.6772	0.59209	-0.5516	0.2634	1.0451	0.70197
5e+12	-0.2737	-0.0326	0.2665	0.25444	-0.3493	-0.09095	0.6274	0.47909	-0.6158	-0.05835	0.8389	0.64238
1e+13	-0.4303	-0.1021	0.2166	0.30085	-0.3837	-0.08755	0.671	0.50784	-0.5784	0.01455	0.9447	0.69861

Device Test: 16.16 LEAK|EN_LEAK/EN/14/14/0/0/5/500kHz//@I_EN_LEAK

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = -100.0, Upper Limit = 700.0 (nA))

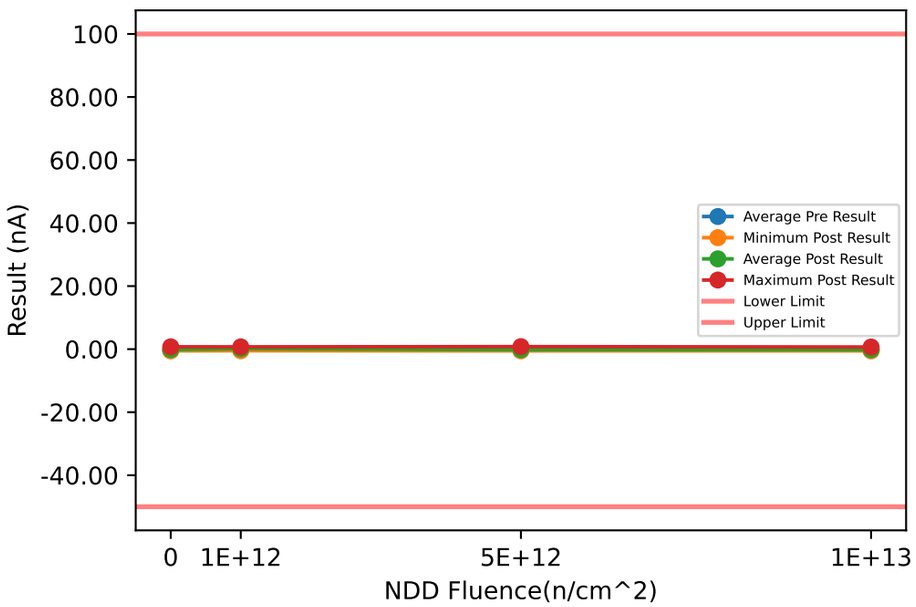
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.0334	0.4354	0.4688
466	1e+12	NDD	-0.074	2.1453	2.2193
762	0	CORRELATION	0.0479	0.5321	0.4842
769	1e+12	NDD	-0.0334	2.0674	2.1008
887	1e+12	NDD	-0.1051	0.0879	0.193
891	0	CORRELATION	0.1167	0.1191	0.0024
927	1e+12	NDD	0.2197	0.267	0.0473
967	5e+12	NDD	-0.1209	1.7245	1.8454
1204	1e+13	NDD	0.5131	0.5657	0.0526
1284	1e+13	NDD	0.4316	0.878	0.4464
1292	5e+12	NDD	0.1323	0.1785	0.0462
1364	1e+13	NDD	0.9321	1.3741	0.442
1383	5e+12	NDD	-0.0676	0.4915	0.5591
1388	5e+12	NDD	-0.1957	0.2607	0.4564
1427	1e+13	NDD	-0.0145	2.2357	2.2502
1666	0	CORRELATION	-0.3272	2.0455	2.3727

Test Statistics (nA)

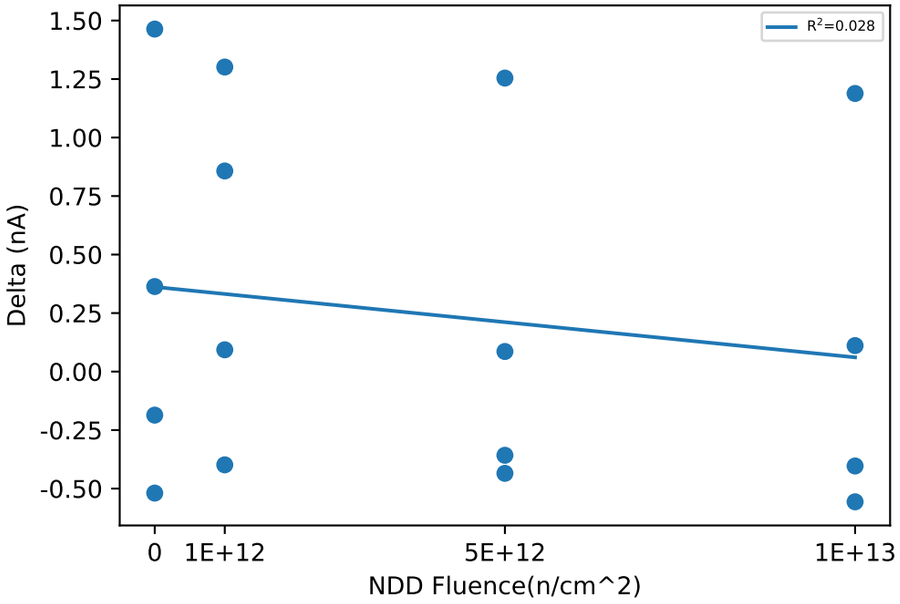
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3272	-0.049	0.1167	0.19535	0.1191	0.78303	2.0455	0.85993	0.0024	0.83203	2.3727	1.0512
1e+12	-0.1051	0.0018	0.2197	0.1482	0.0879	1.1419	2.1453	1.1165	0.0473	1.1401	2.2193	1.1802
5e+12	-0.1957	-0.062975	0.1323	0.14039	0.1785	0.6638	1.7245	0.71944	0.0462	0.72677	1.8454	0.77797
1e+13	-0.0145	0.46558	0.9321	0.38796	0.5657	1.2634	2.2357	0.72868	0.0526	0.7978	2.2502	0.98571

Device Test: 16.17 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK_1V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = -50.0, Upper Limit = 100.0 (nA))

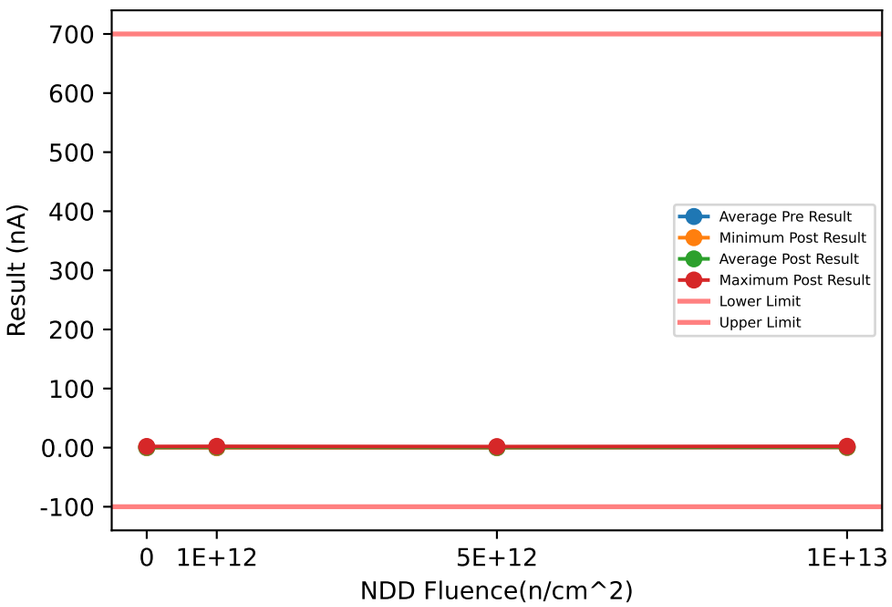
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.2019	-0.388	-0.1861
466	1e+12	NDD	-0.1426	0.7146	0.8572
762	0	CORRELATION	-0.6734	-0.31	0.3634
769	1e+12	NDD	-0.6334	0.6679	1.3013
887	1e+12	NDD	-0.5954	-0.5023	0.0931
891	0	CORRELATION	-0.0175	-0.5367	-0.5192
927	1e+12	NDD	-0.0082	-0.4067	-0.3985
967	5e+12	NDD	-0.4678	0.7863	1.2541
1204	1e+13	NDD	0.0105	-0.546	-0.5565
1284	1e+13	NDD	-0.0927	-0.4961	-0.4034
1292	5e+12	NDD	-0.0238	-0.4586	-0.4348
1364	1e+13	NDD	-0.4834	-0.3724	0.111
1383	5e+12	NDD	-0.6235	-0.5377	0.0858
1388	5e+12	NDD	-0.102	-0.4597	-0.3577
1427	1e+13	NDD	-0.5204	0.6679	1.1883
1666	0	CORRELATION	-0.7302	0.7333	1.4635

Test Statistics (nA)

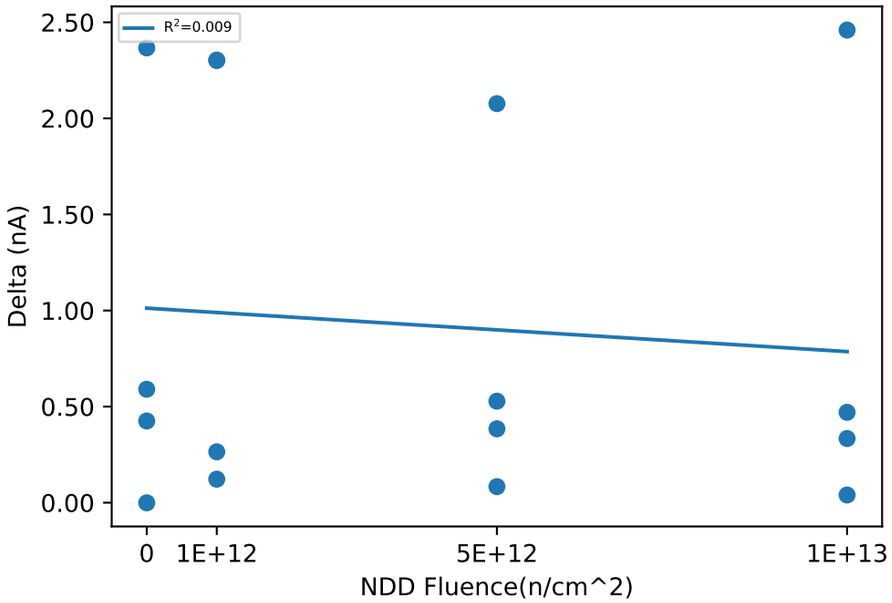
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.7302	-0.40575	-0.0175	0.35081	-0.5367	-0.12535	0.7333	0.58011	-0.5192	0.2804	1.4635	0.86864
1e+12	-0.6334	-0.3449	-0.0082	0.31637	-0.5023	0.11838	0.7146	0.66292	-0.3985	0.46327	1.3013	0.76095
5e+12	-0.6235	-0.30428	-0.0238	0.28765	-0.5377	-0.16742	0.7863	0.63689	-0.4348	0.13685	1.2541	0.77936
1e+13	-0.5204	-0.2715	0.0105	0.26978	-0.546	-0.18665	0.6679	0.57435	-0.5565	0.08485	1.1883	0.78909

Device Test: 16.18 LEAK|EN_LEAK/EN/14/14/0/1000/5/500kHz//@I_EN_LEAK

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = -100.0, Upper Limit = 700.0 (nA))

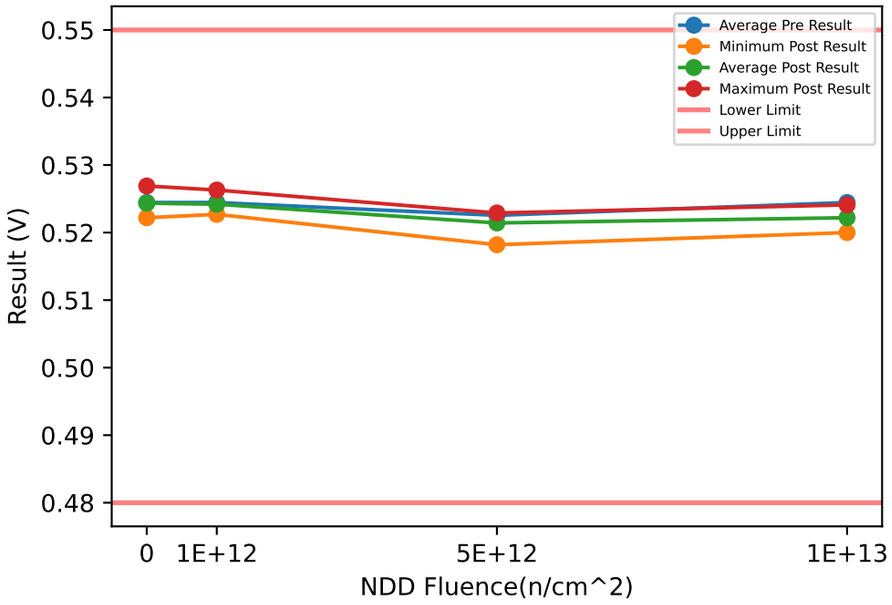
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.1707	0.2545	0.4252
466	1e+12	NDD	-0.1426	2.1609	2.3035
762	0	CORRELATION	-0.0926	0.4977	0.5903
769	1e+12	NDD	-0.2897	2.0113	2.301
887	1e+12	NDD	-0.2987	-0.0339	0.2648
891	0	CORRELATION	0.023	0.0223	-0.0007
927	1e+12	NDD	-0.0082	0.1141	0.1223
967	5e+12	NDD	-0.3053	1.7713	2.0766
1204	1e+13	NDD	0.357	0.3971	0.0401
1284	1e+13	NDD	0.3411	0.675	0.3339
1292	5e+12	NDD	-0.0675	0.0161	0.0836
1364	1e+13	NDD	0.8134	1.2837	0.4703
1383	5e+12	NDD	-0.0801	0.3044	0.3845
1388	5e+12	NDD	-0.3361	0.1921	0.5282
1427	1e+13	NDD	-0.2425	2.217	2.4595
1666	0	CORRELATION	-0.4022	1.9645	2.3667

Test Statistics (nA)

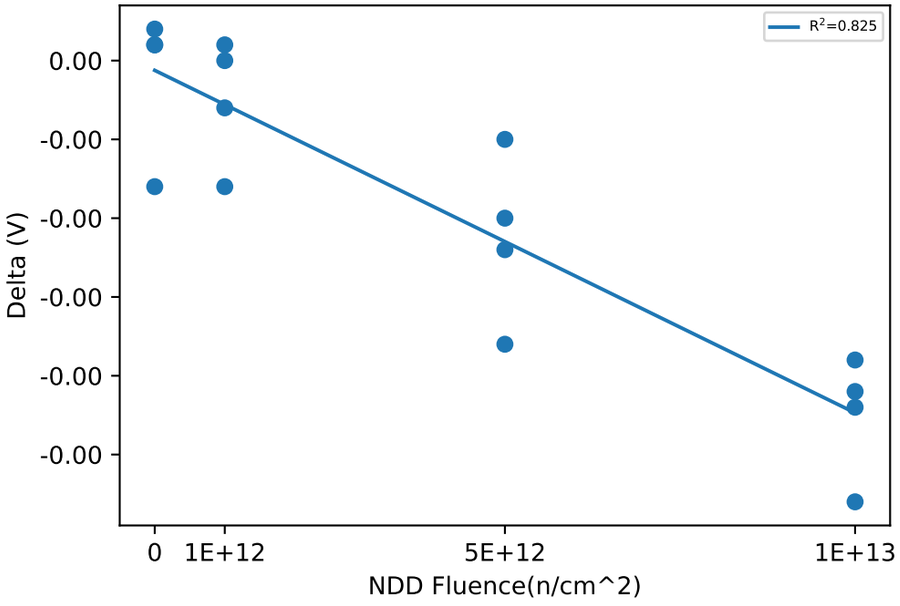
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.4022	-0.16062	0.023	0.17963	0.0223	0.68475	1.9645	0.87497	-0.0007	0.84537	2.3667	1.0443
1e+12	-0.2987	-0.1848	-0.0082	0.13777	-0.0339	1.0631	2.1609	1.1844	0.1223	1.2479	2.3035	1.2188
5e+12	-0.3361	-0.19725	-0.0675	0.14319	0.0161	0.57098	1.7713	0.80897	0.0836	0.76822	2.0766	0.8917
1e+13	-0.2425	0.31725	0.8134	0.43268	0.3971	1.1432	2.217	0.80595	0.0401	0.82595	2.4595	1.1037

Device Test: 16.2 LEVEL|EN_FALL/EN/4.5/4.5/0/0/4.5/500kHz//@V_EN_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

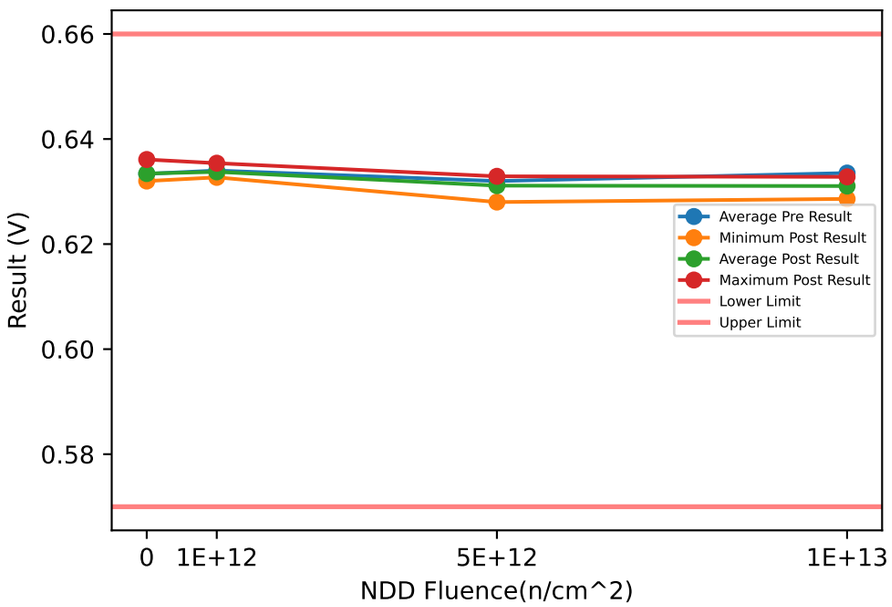
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5226	0.5228	0.0002
466	1e+12	NDD	0.5235	0.5227	-0.0008
762	0	CORRELATION	0.5254	0.5255	0.0001
769	1e+12	NDD	0.5242	0.5242	0
887	1e+12	NDD	0.5262	0.5263	0.0001
891	0	CORRELATION	0.5268	0.5269	0.0001
927	1e+12	NDD	0.5239	0.5236	-0.0003
967	5e+12	NDD	0.5194	0.5182	-0.0012
1204	1e+13	NDD	0.5222	0.52	-0.0022
1284	1e+13	NDD	0.5247	0.5226	-0.0021
1292	5e+12	NDD	0.5228	0.5223	-0.0005
1364	1e+13	NDD	0.5249	0.5221	-0.0028
1383	5e+12	NDD	0.5239	0.5229	-0.001
1388	5e+12	NDD	0.5241	0.5223	-0.0018
1427	1e+13	NDD	0.526	0.5241	-0.0019
1666	0	CORRELATION	0.523	0.5222	-0.0008

Test Statistics (V)

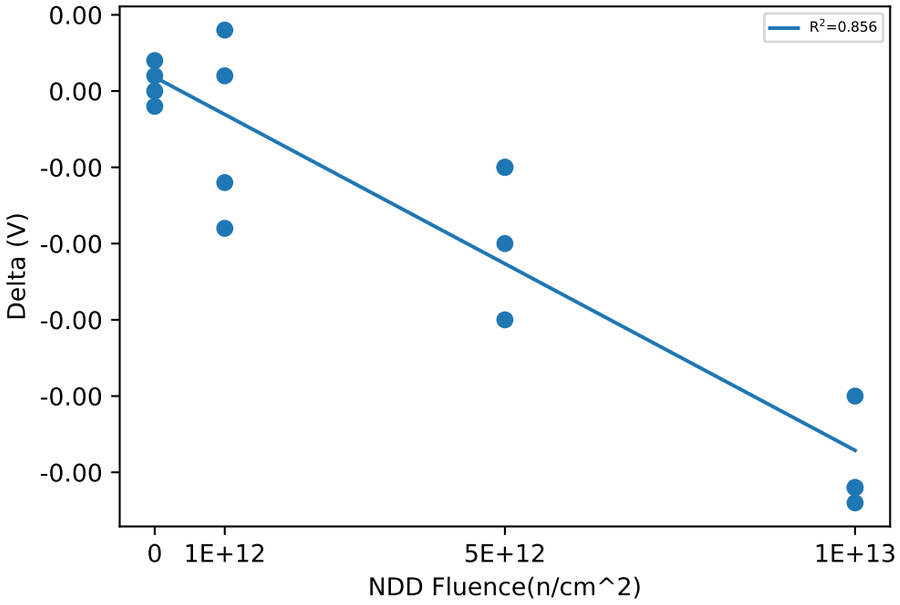
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5226	0.52445	0.5268	0.0019958	0.5222	0.52435	0.5269	0.0022249	-0.0008	-0.0001	0.0002	0.00046904
1e+12	0.5235	0.52445	0.5262	0.0012014	0.5227	0.5242	0.5263	0.0015297	-0.0008	-0.00025	0.0001	0.00040415
5e+12	0.5194	0.52255	0.5241	0.0021764	0.5182	0.52143	0.5229	0.0021685	-0.0018	-0.001125	-0.0005	0.00053774
1e+13	0.5222	0.52445	0.526	0.0016052	0.52	0.5222	0.5241	0.0016951	-0.0028	-0.00225	-0.0019	0.0003873

Device Test: 16.4 LEVEL|EN_RISE/EN/5/5/0/0/5/500kHz//@V_EN_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

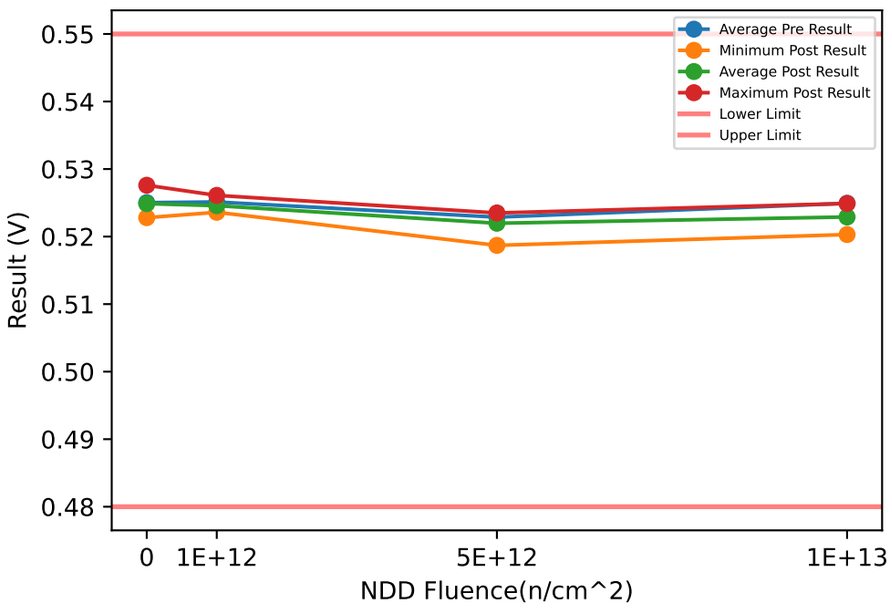
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6319	0.6321	0.0002
466	1e+12	NDD	0.6326	0.6327	0.0001
762	0	CORRELATION	0.6334	0.6335	0.0001
769	1e+12	NDD	0.6342	0.6333	-0.0009
887	1e+12	NDD	0.636	0.6354	-0.0006
891	0	CORRELATION	0.6362	0.6361	-0.0001
927	1e+12	NDD	0.6332	0.6336	0.0004
967	5e+12	NDD	0.6295	0.628	-0.0015
1204	1e+13	NDD	0.6312	0.6286	-0.0026
1284	1e+13	NDD	0.6334	0.6314	-0.002
1292	5e+12	NDD	0.632	0.6315	-0.0005
1364	1e+13	NDD	0.634	0.6314	-0.0026
1383	5e+12	NDD	0.6334	0.6329	-0.0005
1388	5e+12	NDD	0.6331	0.6321	-0.001
1427	1e+13	NDD	0.6355	0.6328	-0.0027
1666	0	CORRELATION	0.632	0.632	0

Test Statistics (V)

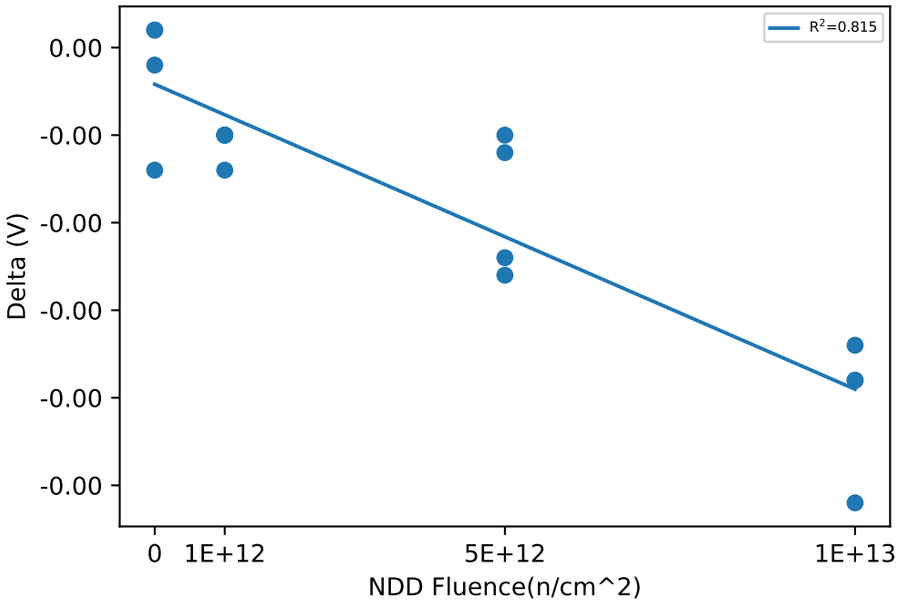
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6319	0.63338	0.6362	0.002004	0.632	0.63343	0.6361	0.0019103	-0.0001	5e-05	0.0002	0.0001291
1e+12	0.6326	0.634	0.636	0.0014877	0.6327	0.63375	0.6354	0.0011619	-0.0009	-0.00025	0.0004	0.00060277
5e+12	0.6295	0.632	0.6334	0.001772	0.628	0.63112	0.6329	0.0021608	-0.0015	-0.000875	-0.0005	0.00047871
1e+13	0.6312	0.63353	0.6355	0.001784	0.6286	0.63105	0.6328	0.0017616	-0.0027	-0.002475	-0.002	0.00032016

Device Test: 16.5 LEVEL|EN_FALL/EN/5/5/0/0/5/500kHz//@V_EN_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

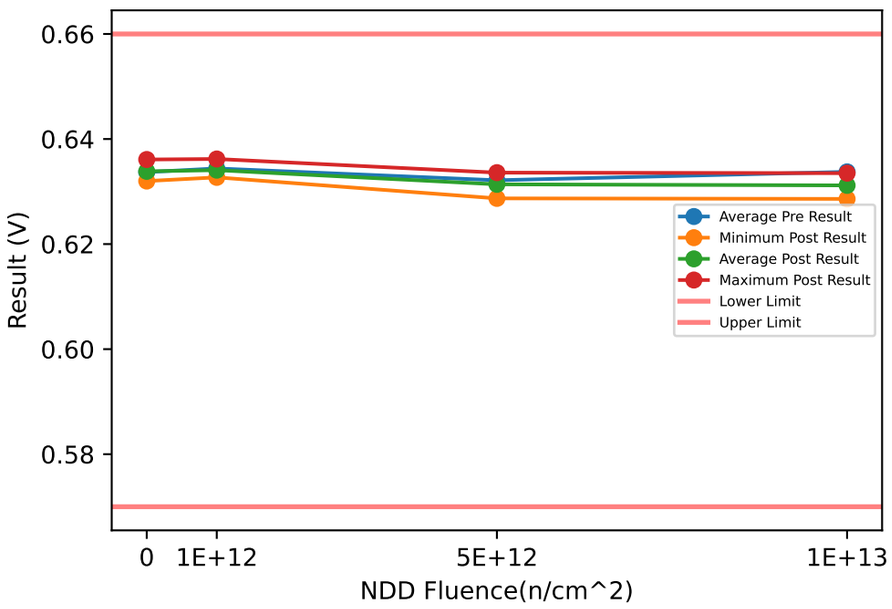
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5235	0.5236	0.0001
466	1e+12	NDD	0.5241	0.5236	-0.0005
762	0	CORRELATION	0.5262	0.5255	-0.0007
769	1e+12	NDD	0.5248	0.5243	-0.0005
887	1e+12	NDD	0.5268	0.5261	-0.0007
891	0	CORRELATION	0.5275	0.5276	0.0001
927	1e+12	NDD	0.5248	0.5243	-0.0005
967	5e+12	NDD	0.52	0.5187	-0.0013
1204	1e+13	NDD	0.522	0.5203	-0.0017
1284	1e+13	NDD	0.5247	0.5228	-0.0019
1292	5e+12	NDD	0.5234	0.5228	-0.0006
1364	1e+13	NDD	0.5262	0.5236	-0.0026
1383	5e+12	NDD	0.524	0.5235	-0.0005
1388	5e+12	NDD	0.5241	0.5229	-0.0012
1427	1e+13	NDD	0.5268	0.5249	-0.0019
1666	0	CORRELATION	0.5229	0.5228	-0.0001

Test Statistics (V)

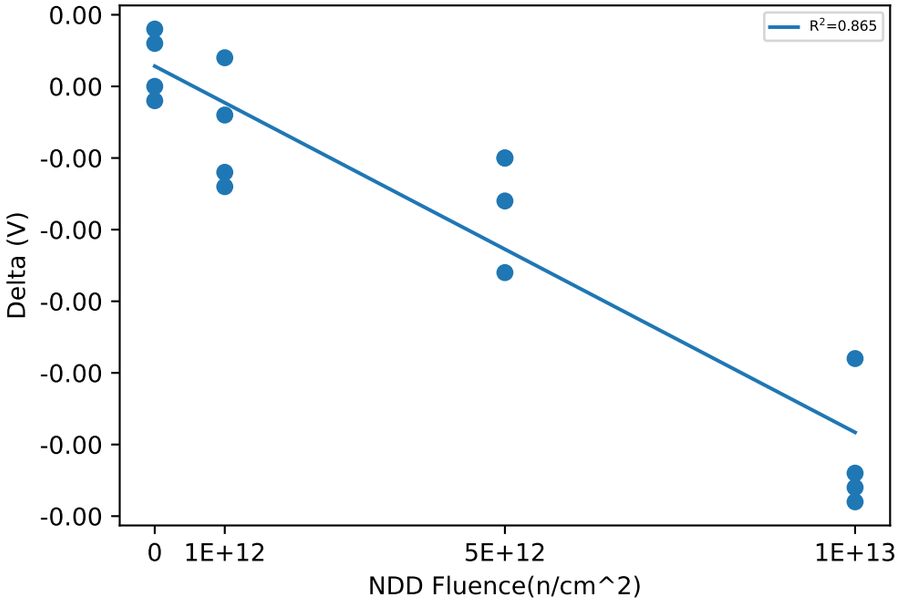
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5229	0.52502	0.5275	0.0021869	0.5228	0.52487	0.5276	0.0021407	-0.0007	-0.00015	0.0001	0.00037859
1e+12	0.5241	0.52513	0.5268	0.0011644	0.5236	0.52458	0.5261	0.0010689	-0.0007	-0.00055	-0.0005	0.0001
5e+12	0.52	0.52287	0.5241	0.0019414	0.5187	0.52198	0.5235	0.0022051	-0.0013	-0.0009	-0.0005	0.00040825
1e+13	0.522	0.52493	0.5268	0.0021407	0.5203	0.5229	0.5249	0.0019374	-0.0026	-0.002025	-0.0017	0.00039476

Device Test: 16.7 LEVEL|EN_RISE/EN/12/12/0/0/5/500kHz//@V_EN_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.57, Upper Limit = 0.66 (V))

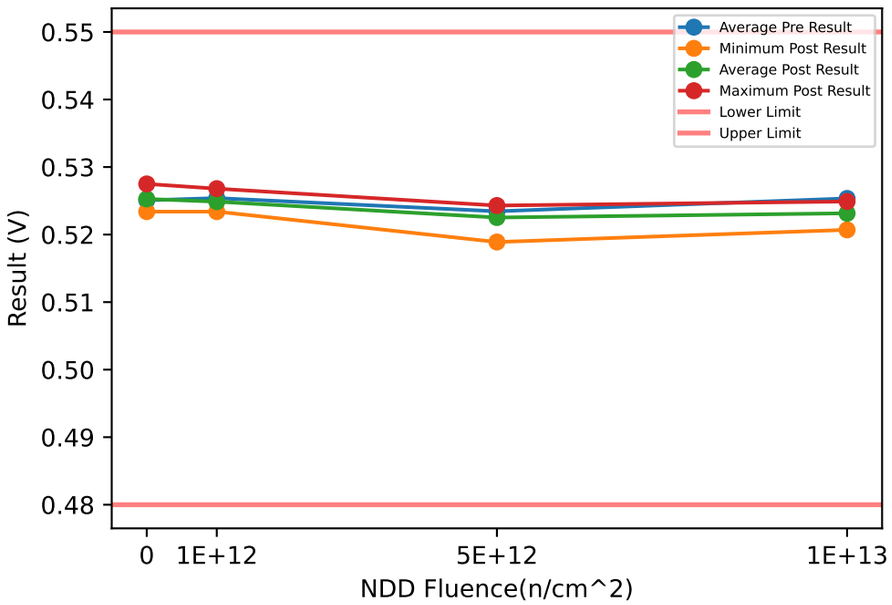
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6326	0.6329	0.0003
466	1e+12	NDD	0.6333	0.6327	-0.0006
762	0	CORRELATION	0.634	0.6344	0.0004
769	1e+12	NDD	0.6341	0.6339	-0.0002
887	1e+12	NDD	0.636	0.6362	0.0002
891	0	CORRELATION	0.6361	0.6361	0
927	1e+12	NDD	0.6342	0.6335	-0.0007
967	5e+12	NDD	0.6292	0.6287	-0.0005
1204	1e+13	NDD	0.6315	0.6286	-0.0029
1284	1e+13	NDD	0.634	0.6312	-0.0028
1292	5e+12	NDD	0.632	0.6312	-0.0008
1364	1e+13	NDD	0.6341	0.6314	-0.0027
1383	5e+12	NDD	0.6341	0.6336	-0.0005
1388	5e+12	NDD	0.6333	0.632	-0.0013
1427	1e+13	NDD	0.6354	0.6335	-0.0019
1666	0	CORRELATION	0.6321	0.632	-0.0001

Test Statistics (V)

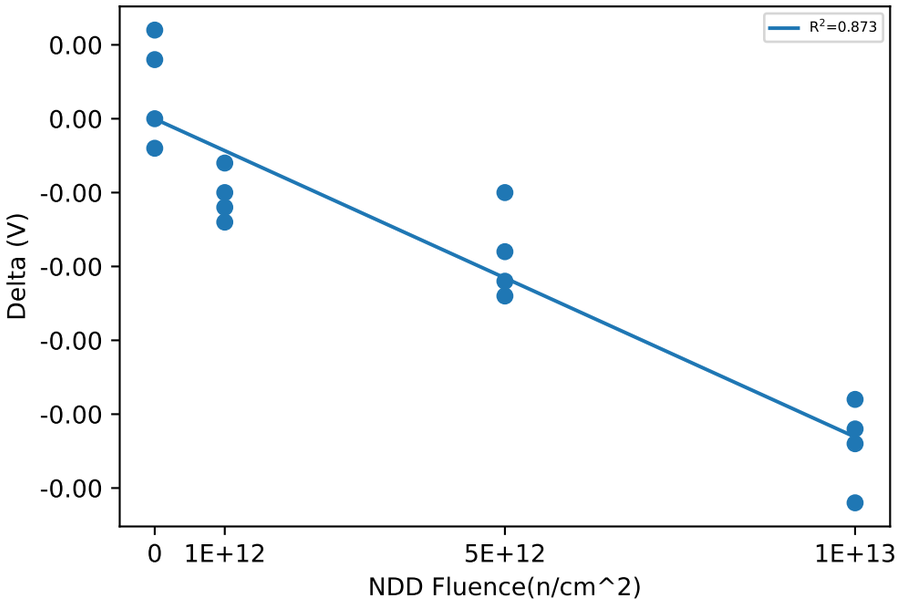
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6321	0.6337	0.6361	0.0017907	0.632	0.63385	0.6361	0.0017972	-0.0001	0.00015	0.0004	0.00023805
1e+12	0.6333	0.6344	0.636	0.0011402	0.6327	0.63407	0.6362	0.0015019	-0.0007	-0.000325	0.0002	0.0004113
5e+12	0.6292	0.63215	0.6341	0.0021486	0.6287	0.63138	0.6336	0.0020435	-0.0013	-0.000775	-0.0005	0.00037749
1e+13	0.6315	0.63375	0.6354	0.0016299	0.6286	0.63118	0.6335	0.0020073	-0.0029	-0.002575	-0.0019	0.00045735

Device Test: 16.8 LEVEL|EN_FALL/EN/12/12/0/0/5/500kHz//@V_EN_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.48, Upper Limit = 0.55 (V))

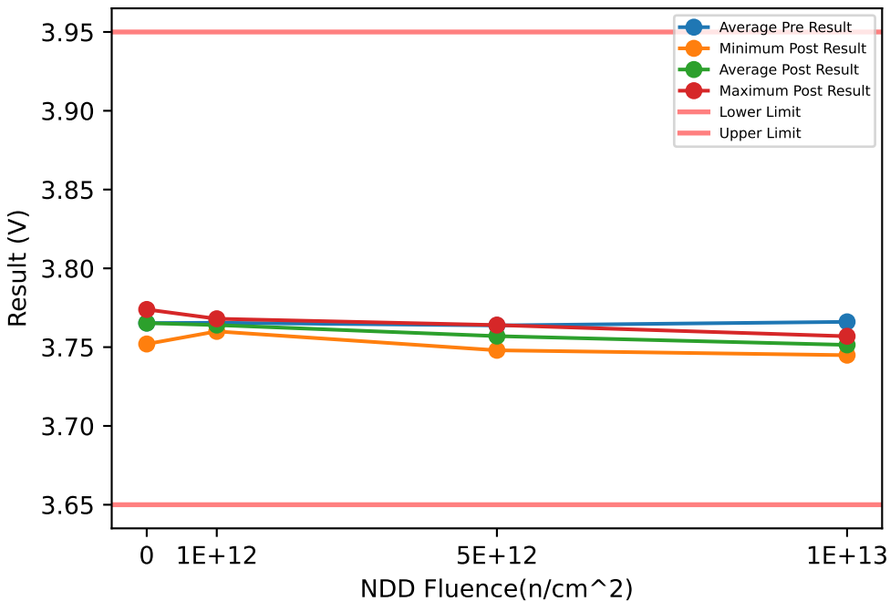
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.524	0.5238	-0.0002
466	1e+12	NDD	0.5241	0.5234	-0.0007
762	0	CORRELATION	0.526	0.5264	0.0004
769	1e+12	NDD	0.5254	0.5249	-0.0005
887	1e+12	NDD	0.5274	0.5268	-0.0006
891	0	CORRELATION	0.5275	0.5275	0
927	1e+12	NDD	0.5247	0.5244	-0.0003
967	5e+12	NDD	0.52	0.5189	-0.0011
1204	1e+13	NDD	0.5229	0.5207	-0.0022
1284	1e+13	NDD	0.5255	0.5234	-0.0021
1292	5e+12	NDD	0.5243	0.5234	-0.0009
1364	1e+13	NDD	0.5262	0.5236	-0.0026
1383	5e+12	NDD	0.5248	0.5243	-0.0005
1388	5e+12	NDD	0.5247	0.5235	-0.0012
1427	1e+13	NDD	0.5268	0.5249	-0.0019
1666	0	CORRELATION	0.5228	0.5234	0.0006

Test Statistics (V)

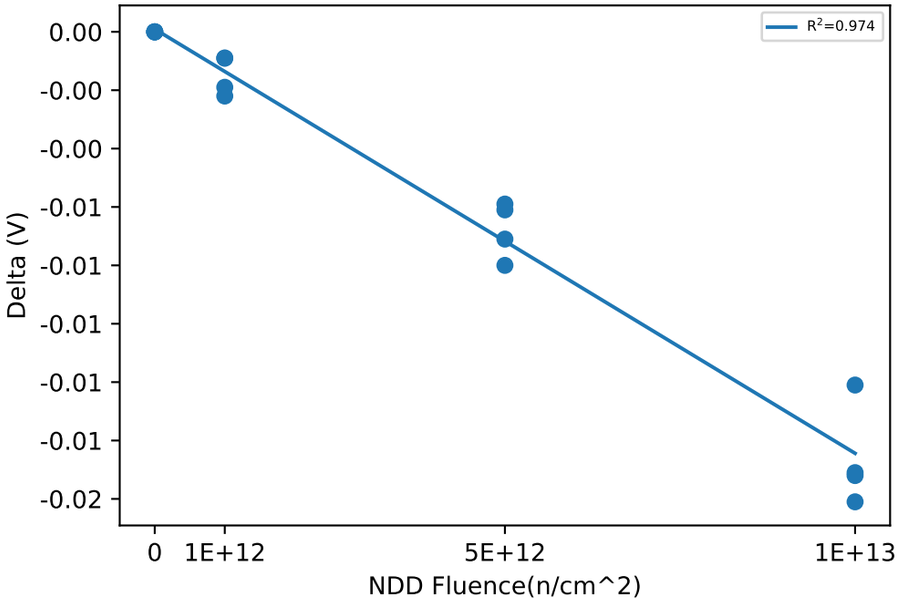
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5228	0.52507	0.5275	0.0020871	0.5234	0.52527	0.5275	0.0019923	-0.0002	0.0002	0.0006	0.00036515
1e+12	0.5241	0.5254	0.5274	0.0014353	0.5234	0.52487	0.5268	0.0014268	-0.0007	-0.000525	-0.0003	0.00017078
5e+12	0.52	0.52345	0.5248	0.0023101	0.5189	0.52253	0.5243	0.00245	-0.0012	-0.000925	-0.0005	0.00030957
1e+13	0.5229	0.52535	0.5268	0.0017176	0.5207	0.52315	0.5249	0.0017635	-0.0026	-0.0022	-0.0019	0.00029439

Device Test: 17.1 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

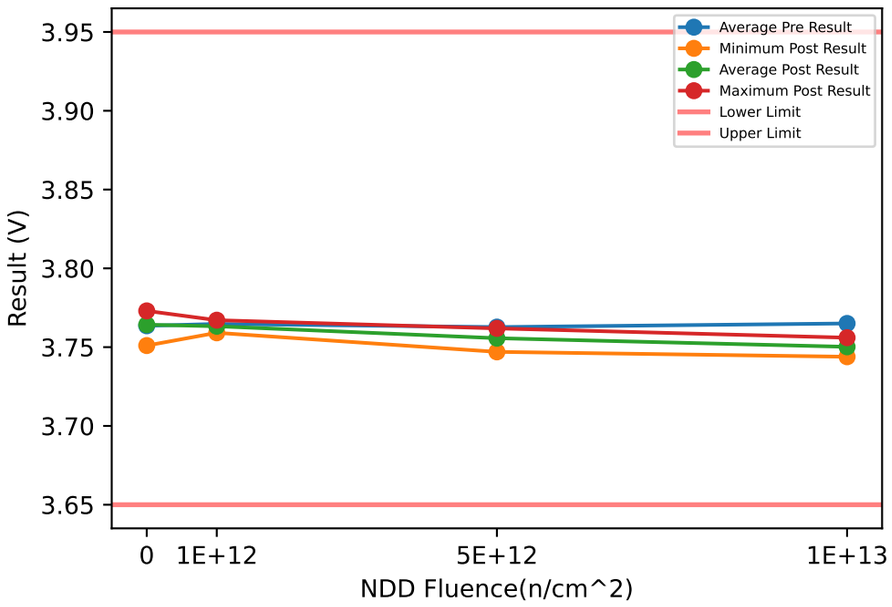
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7739	3.7739	0
466	1e+12	NDD	3.7699	3.768	-0.0019
762	0	CORRELATION	3.7631	3.7631	0
769	1e+12	NDD	3.768	3.7671	-0.0009
887	1e+12	NDD	3.7631	3.7609	-0.0022
891	0	CORRELATION	3.7721	3.7721	0
927	1e+12	NDD	3.7609	3.76	-0.0009
967	5e+12	NDD	3.7541	3.748	-0.0061
1204	1e+13	NDD	3.76	3.7449	-0.0151
1284	1e+13	NDD	3.769	3.7569	-0.0121
1292	5e+12	NDD	3.7699	3.764	-0.0059
1364	1e+13	NDD	3.7721	3.7569	-0.0152
1383	5e+12	NDD	3.7671	3.7591	-0.008
1388	5e+12	NDD	3.764	3.7569	-0.0071
1427	1e+13	NDD	3.7631	3.747	-0.0161
1666	0	CORRELATION	3.752	3.752	0

Test Statistics (V)

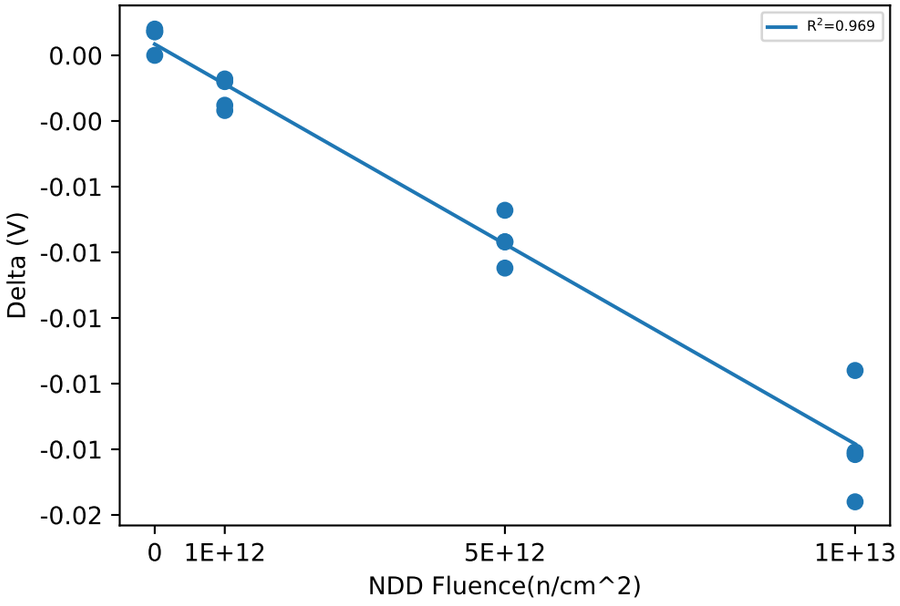
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.752	3.7653	3.7739	0.010032	3.752	3.7653	3.7739	0.010032	0	0	0	0
1e+12	3.7609	3.7655	3.7699	0.0041844	3.76	3.764	3.768	0.004132	-0.0022	-0.001475	-0.0009	0.00067515
5e+12	3.7541	3.7638	3.7699	0.0068854	3.748	3.757	3.764	0.0066938	-0.008	-0.006775	-0.0059	0.00097082
1e+13	3.76	3.766	3.7721	0.0054958	3.7449	3.7514	3.7569	0.0063799	-0.0161	-0.014625	-0.0121	0.0017424

Device Test: 17.10 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

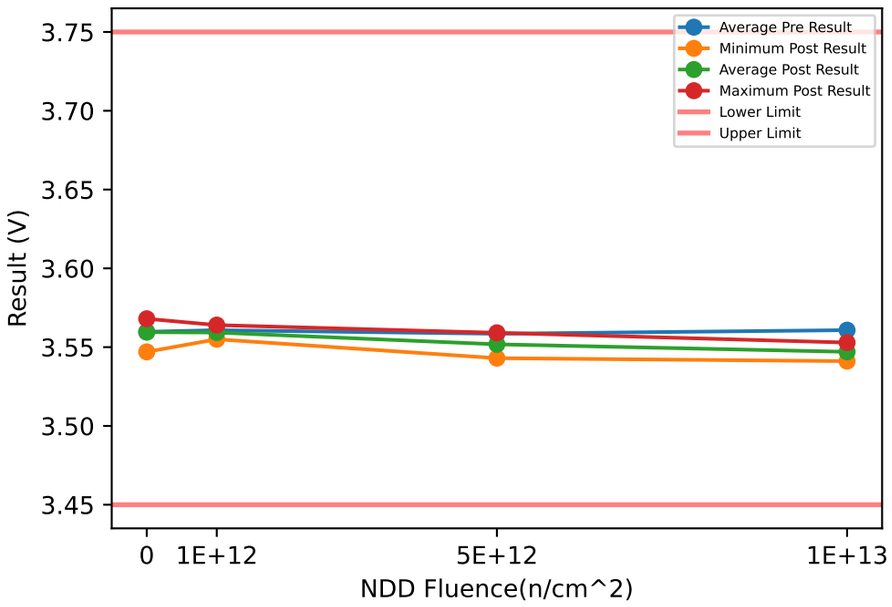
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7721	3.773	0.0009
466	1e+12	NDD	3.769	3.7671	-0.0019
762	0	CORRELATION	3.7609	3.7619	0.001
769	1e+12	NDD	3.768	3.7659	-0.0021
887	1e+12	NDD	3.7619	3.7609	-0.001
891	0	CORRELATION	3.7711	3.7711	0
927	1e+12	NDD	3.76	3.7591	-0.0009
967	5e+12	NDD	3.7529	3.747	-0.0059
1204	1e+13	NDD	3.7591	3.7439	-0.0152
1284	1e+13	NDD	3.768	3.756	-0.012
1292	5e+12	NDD	3.769	3.7619	-0.0071
1364	1e+13	NDD	3.7711	3.756	-0.0151
1383	5e+12	NDD	3.7659	3.7578	-0.0081
1388	5e+12	NDD	3.7631	3.756	-0.0071
1427	1e+13	NDD	3.7619	3.7449	-0.017
1666	0	CORRELATION	3.7501	3.751	0.0009

Test Statistics (V)

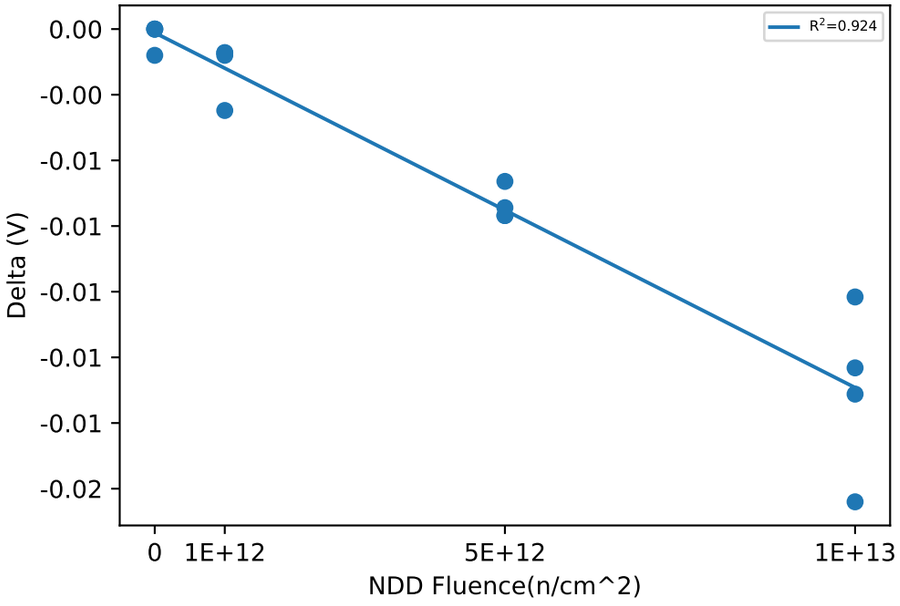
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7501	3.7635	3.7721	0.010296	3.751	3.7643	3.773	0.010076	0	0.0007	0.001	0.00046904
1e+12	3.76	3.7647	3.769	0.0044463	3.7591	3.7633	3.7671	0.0038553	-0.0021	-0.001475	-0.0009	0.00061305
5e+12	3.7529	3.7627	3.769	0.0069792	3.747	3.7557	3.7619	0.0062883	-0.0081	-0.00705	-0.0059	0.0009
1e+13	3.7591	3.765	3.7711	0.0054963	3.7439	3.7502	3.756	0.0067097	-0.017	-0.014825	-0.012	0.0020759

Device Test: 17.11 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/500kHz//@PVIN_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

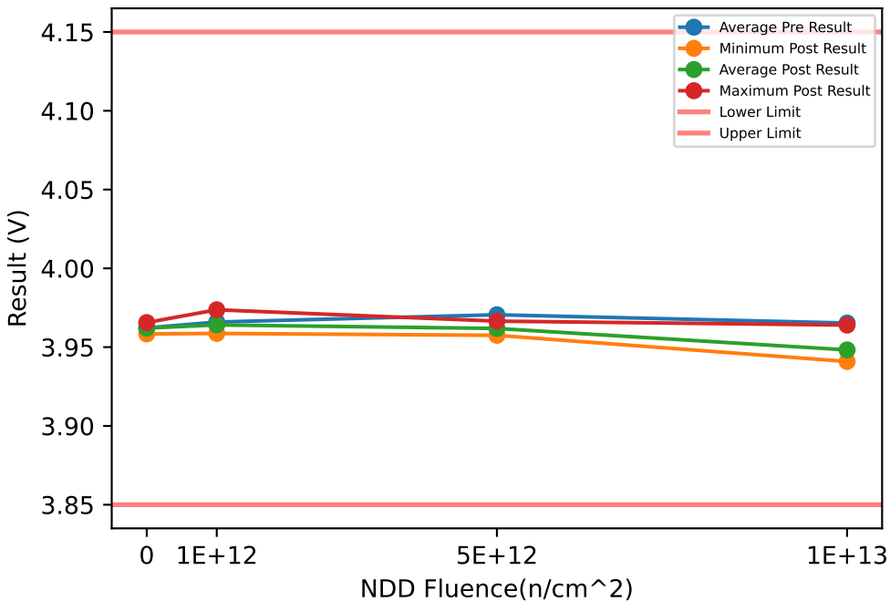
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.568	3.568	0
466	1e+12	NDD	3.5649	3.564	-0.0009
762	0	CORRELATION	3.5581	3.5581	0
769	1e+12	NDD	3.564	3.5631	-0.0009
887	1e+12	NDD	3.5581	3.555	-0.0031
891	0	CORRELATION	3.5659	3.5649	-0.001
927	1e+12	NDD	3.556	3.555	-0.001
967	5e+12	NDD	3.5501	3.543	-0.0071
1204	1e+13	NDD	3.555	3.5421	-0.0129
1284	1e+13	NDD	3.5631	3.5529	-0.0102
1292	5e+12	NDD	3.5649	3.5591	-0.0058
1364	1e+13	NDD	3.5659	3.552	-0.0139
1383	5e+12	NDD	3.5609	3.5541	-0.0068
1388	5e+12	NDD	3.5581	3.551	-0.0071
1427	1e+13	NDD	3.5591	3.5411	-0.018
1666	0	CORRELATION	3.547	3.547	0

Test Statistics (V)

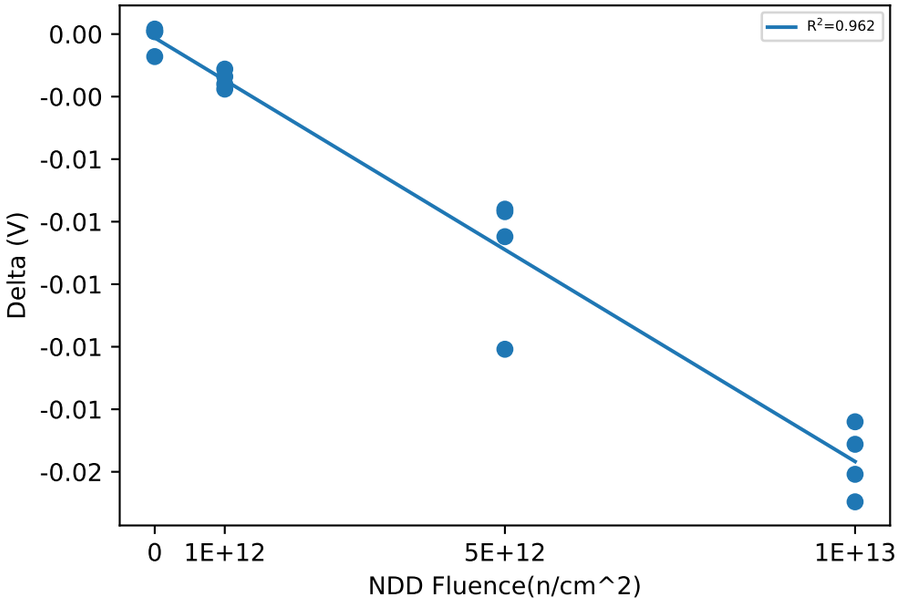
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.547	3.5598	3.568	0.0095074	3.547	3.5595	3.568	0.0093027	-0.001	-0.00025	0	0.0005
1e+12	3.556	3.5608	3.5649	0.004373	3.555	3.5593	3.564	0.00495	-0.0031	-0.001475	-0.0009	0.0010844
5e+12	3.5501	3.5585	3.5649	0.0062567	3.543	3.5518	3.5591	0.0067493	-0.0071	-0.0067	-0.0058	0.00061644
1e+13	3.555	3.5608	3.5659	0.0047549	3.5411	3.547	3.5529	0.0062883	-0.018	-0.01375	-0.0102	0.0032357

Device Test: 17.13 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

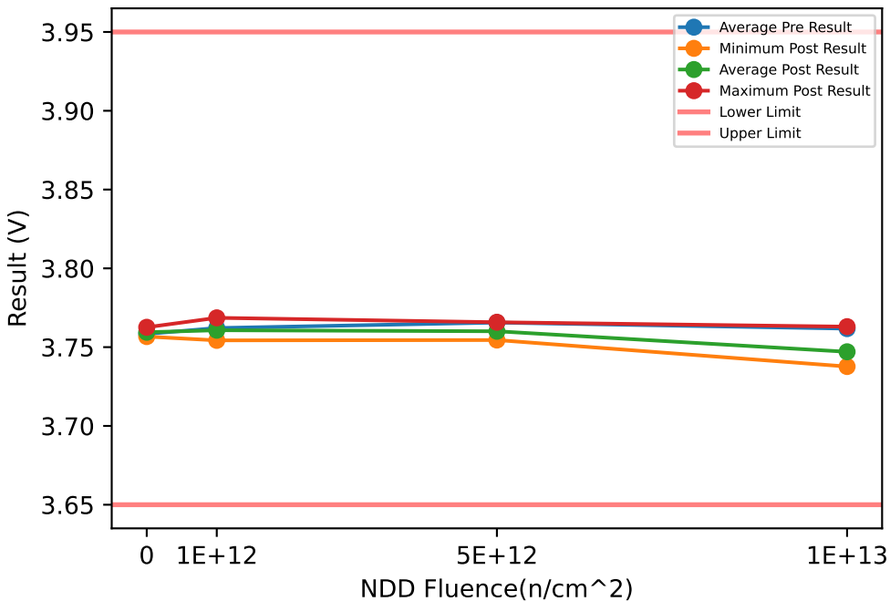
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.9643	3.9634	-0.0009
466	1e+12	NDD	3.9662	3.964	-0.0022
762	0	CORRELATION	3.9583	3.9584	0.0001
769	1e+12	NDD	3.9604	3.9587	-0.0017
887	1e+12	NDD	3.9751	3.9737	-0.0014
891	0	CORRELATION	3.9655	3.9656	0.0001
927	1e+12	NDD	3.962	3.96	-0.002
967	5e+12	NDD	3.9729	3.9603	-0.0126
1204	1e+13	NDD	3.9573	3.9409	-0.0164
1284	1e+13	NDD	3.9656	3.9469	-0.0187
1292	5e+12	NDD	3.9736	3.9665	-0.0071
1364	1e+13	NDD	3.9588	3.9412	-0.0176
1383	5e+12	NDD	3.9645	3.9575	-0.007
1388	5e+12	NDD	3.9712	3.9631	-0.0081
1427	1e+13	NDD	3.9795	3.964	-0.0155
1666	0	CORRELATION	3.9607	3.9609	0.0002

Test Statistics (V)

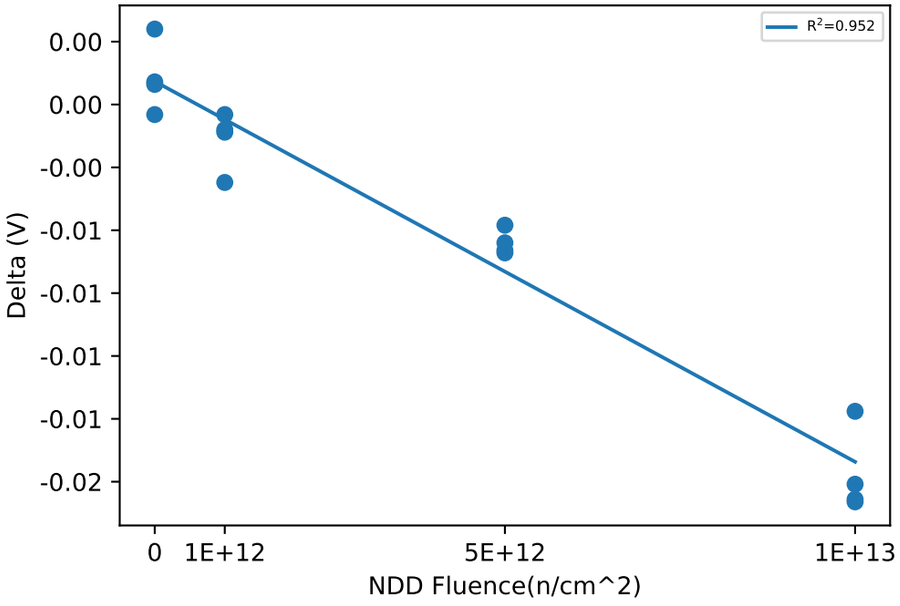
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9583	3.9622	3.9655	0.0033045	3.9584	3.9621	3.9656	0.0031127	-0.0009	-0.000125	0.0002	0.00051881
1e+12	3.9604	3.9659	3.9751	0.0065876	3.9587	3.9641	3.9737	0.0067858	-0.0022	-0.001825	-0.0014	0.00035
5e+12	3.9645	3.9706	3.9736	0.0041573	3.9575	3.9619	3.9665	0.0038518	-0.0126	-0.0087	-0.007	0.002647
1e+13	3.9573	3.9653	3.9795	0.010132	3.9409	3.9482	3.964	0.010857	-0.0187	-0.01705	-0.0155	0.0013964

Device Test: 17.14 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/500kHz//@VIN_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

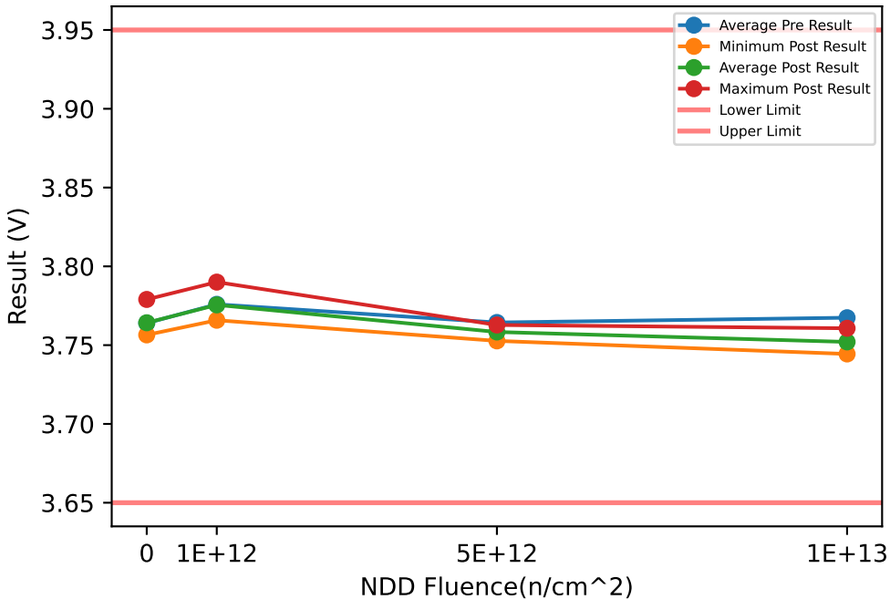
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7617	3.7626	0.0009
466	1e+12	NDD	3.7633	3.7602	-0.0031
762	0	CORRELATION	3.7559	3.7567	0.0008
769	1e+12	NDD	3.7553	3.7543	-0.001
887	1e+12	NDD	3.769	3.7686	-0.0004
891	0	CORRELATION	3.7581	3.7611	0.003
927	1e+12	NDD	3.7609	3.7598	-0.0011
967	5e+12	NDD	3.7641	3.7583	-0.0058
1204	1e+13	NDD	3.7534	3.7377	-0.0157
1284	1e+13	NDD	3.7567	3.7445	-0.0122
1292	5e+12	NDD	3.7706	3.7658	-0.0048
1364	1e+13	NDD	3.7588	3.743	-0.0158
1383	5e+12	NDD	3.76	3.7545	-0.0055
1388	5e+12	NDD	3.7676	3.7617	-0.0059
1427	1e+13	NDD	3.7781	3.763	-0.0151
1666	0	CORRELATION	3.7578	3.7574	-0.0004

Test Statistics (V)

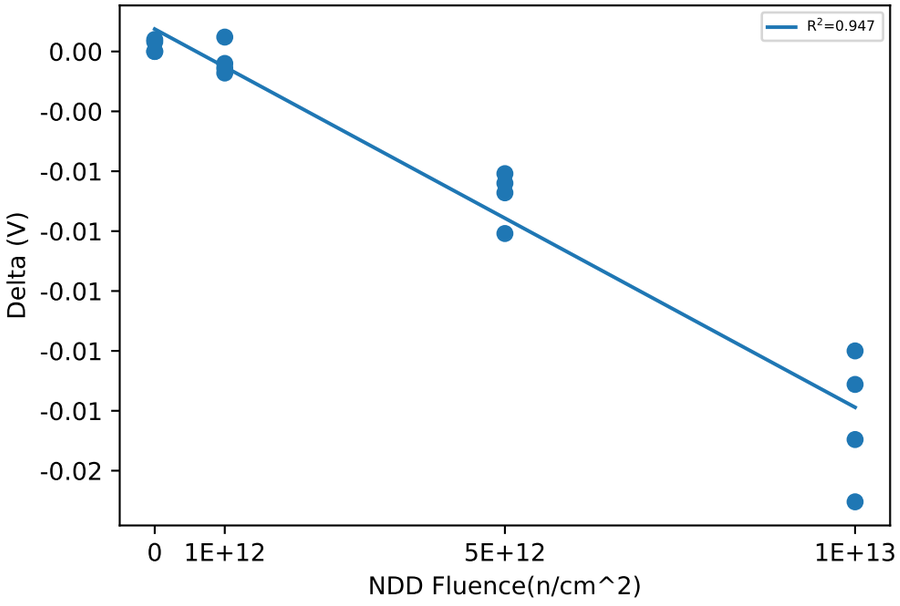
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7559	3.7584	3.7617	0.0024213	3.7567	3.7595	3.7626	0.0028525	-0.0004	0.001075	0.003	0.0014127
1e+12	3.7553	3.7621	3.769	0.0056782	3.7543	3.7607	3.7686	0.0058999	-0.0031	-0.0014	-0.0004	0.0011747
5e+12	3.76	3.7656	3.7706	0.0045683	3.7545	3.7601	3.7658	0.0048183	-0.0059	-0.0055	-0.0048	0.00049666
1e+13	3.7534	3.7618	3.7781	0.011124	3.7377	3.747	3.763	0.011026	-0.0158	-0.0147	-0.0122	0.0016951

Device Test: 17.16 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

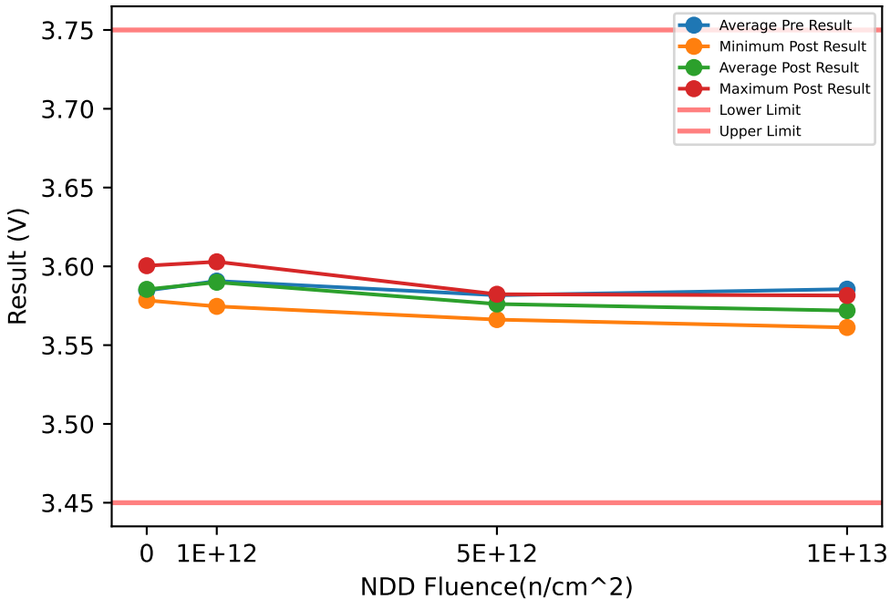
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7786	3.779	0.0004
466	1e+12	NDD	3.7667	3.7658	-0.0009
762	0	CORRELATION	3.761	3.7615	0.0005
769	1e+12	NDD	3.7712	3.7718	0.0006
887	1e+12	NDD	3.775	3.7745	-0.0005
891	0	CORRELATION	3.7598	3.7598	0
927	1e+12	NDD	3.7907	3.79	-0.0007
967	5e+12	NDD	3.7603	3.7527	-0.0076
1204	1e+13	NDD	3.7692	3.7504	-0.0188
1284	1e+13	NDD	3.7732	3.7607	-0.0125
1292	5e+12	NDD	3.7664	3.7613	-0.0051
1364	1e+13	NDD	3.7606	3.7444	-0.0162
1383	5e+12	NDD	3.7625	3.7566	-0.0059
1388	5e+12	NDD	3.7683	3.7628	-0.0055
1427	1e+13	NDD	3.7666	3.7527	-0.0139
1666	0	CORRELATION	3.7565	3.7565	0

Test Statistics (V)

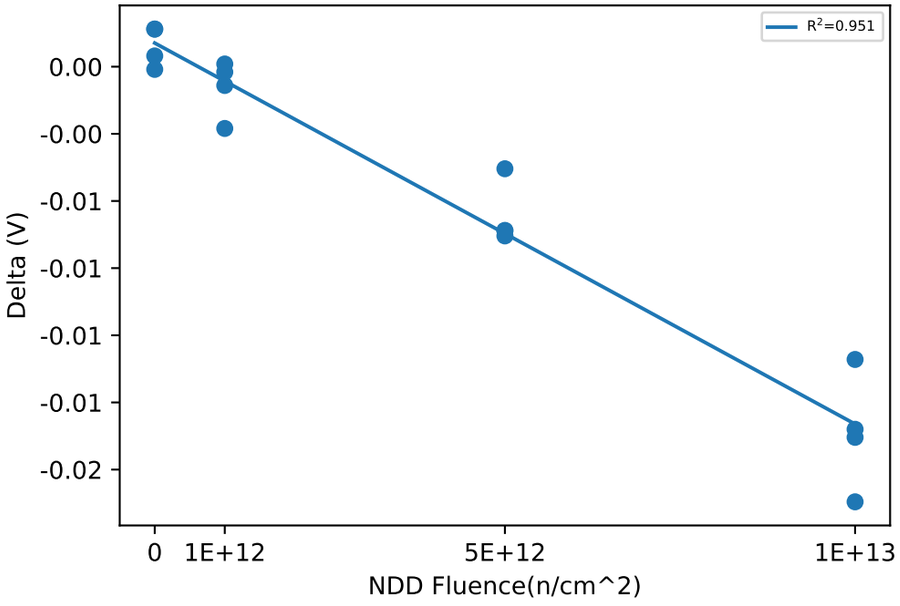
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7565	3.764	3.7786	0.0099339	3.7565	3.7642	3.779	0.010083	0	0.000225	0.0005	0.000263
1e+12	3.7667	3.7759	3.7907	0.010434	3.7658	3.7755	3.79	0.010312	-0.0009	-0.000375	0.0006	0.0006702
5e+12	3.7603	3.7644	3.7683	0.0036344	3.7527	3.7584	3.7628	0.0046004	-0.0076	-0.006025	-0.0051	0.0010996
1e+13	3.7606	3.7674	3.7732	0.0052839	3.7444	3.7521	3.7607	0.0067451	-0.0188	-0.01535	-0.0125	0.0027598

Device Test: 17.17 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/500kHz//@VLDO_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

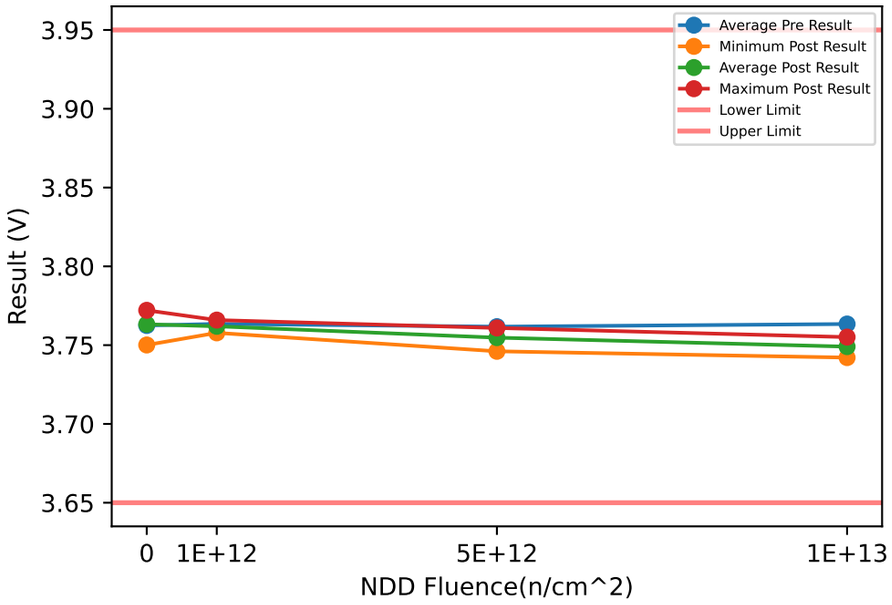
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.599	3.6004	0.0014
466	1e+12	NDD	3.5753	3.5746	-0.0007
762	0	CORRELATION	3.5771	3.5785	0.0014
769	1e+12	NDD	3.5929	3.5906	-0.0023
887	1e+12	NDD	3.5914	3.5915	0.0001
891	0	CORRELATION	3.5844	3.5843	-0.0001
927	1e+12	NDD	3.6031	3.6029	-0.0002
967	5e+12	NDD	3.5723	3.5662	-0.0061
1204	1e+13	NDD	3.5819	3.5684	-0.0135
1284	1e+13	NDD	3.5924	3.5815	-0.0109
1292	5e+12	NDD	3.579	3.5752	-0.0038
1364	1e+13	NDD	3.5904	3.5766	-0.0138
1383	5e+12	NDD	3.5886	3.5823	-0.0063
1388	5e+12	NDD	3.5868	3.5807	-0.0061
1427	1e+13	NDD	3.5774	3.5612	-0.0162
1666	0	CORRELATION	3.578	3.5784	0.0004

Test Statistics (V)

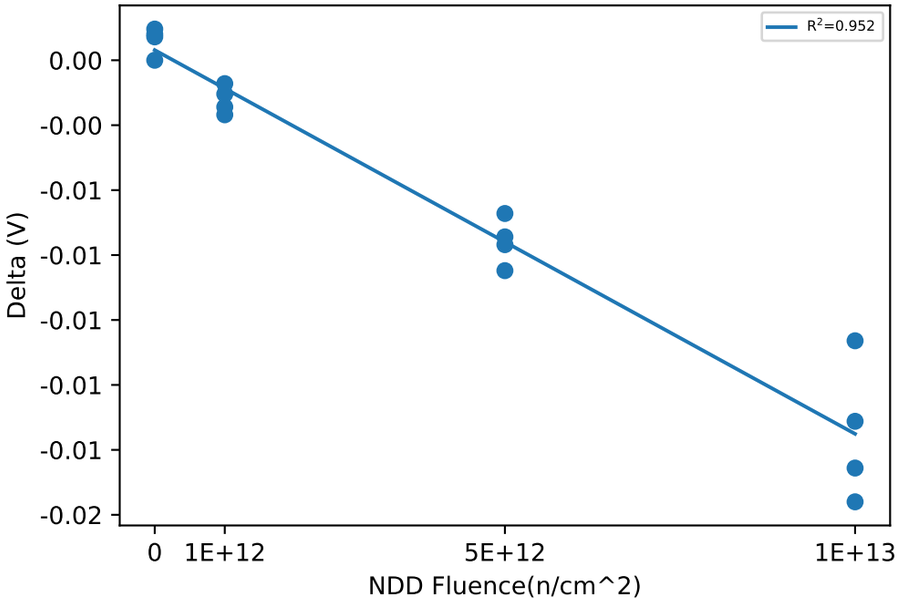
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5771	3.5846	3.599	0.010119	3.5784	3.5854	3.6004	0.010373	-0.0001	0.000775	0.0014	0.00075
1e+12	3.5753	3.5907	3.6031	0.011493	3.5746	3.5899	3.6029	0.011635	-0.0023	-0.000775	0.0001	0.0010689
5e+12	3.5723	3.5817	3.5886	0.0075115	3.5662	3.5761	3.5823	0.0072668	-0.0063	-0.005575	-0.0038	0.0011871
1e+13	3.5774	3.5855	3.5924	0.0070755	3.5612	3.5719	3.5815	0.0089627	-0.0162	-0.0136	-0.0109	0.0021679

Device Test: 17.19 UVLO|PVIN_RISE/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

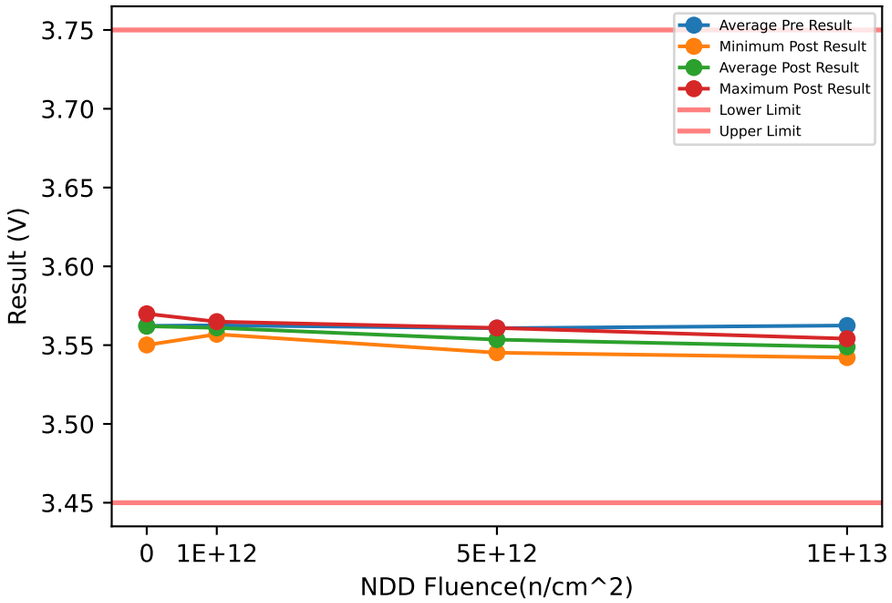
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7711	3.7721	0.001
466	1e+12	NDD	3.768	3.7659	-0.0021
762	0	CORRELATION	3.76	3.7609	0.0009
769	1e+12	NDD	3.7659	3.765	-0.0009
887	1e+12	NDD	3.7609	3.7591	-0.0018
891	0	CORRELATION	3.7699	3.7699	0
927	1e+12	NDD	3.7591	3.7578	-0.0013
967	5e+12	NDD	3.752	3.7461	-0.0059
1204	1e+13	NDD	3.7578	3.7421	-0.0157
1284	1e+13	NDD	3.7659	3.7551	-0.0108
1292	5e+12	NDD	3.768	3.7609	-0.0071
1364	1e+13	NDD	3.769	3.7551	-0.0139
1383	5e+12	NDD	3.765	3.7569	-0.0081
1388	5e+12	NDD	3.7619	3.7551	-0.0068
1427	1e+13	NDD	3.7609	3.7439	-0.017
1666	0	CORRELATION	3.7489	3.7501	0.0012

Test Statistics (V)

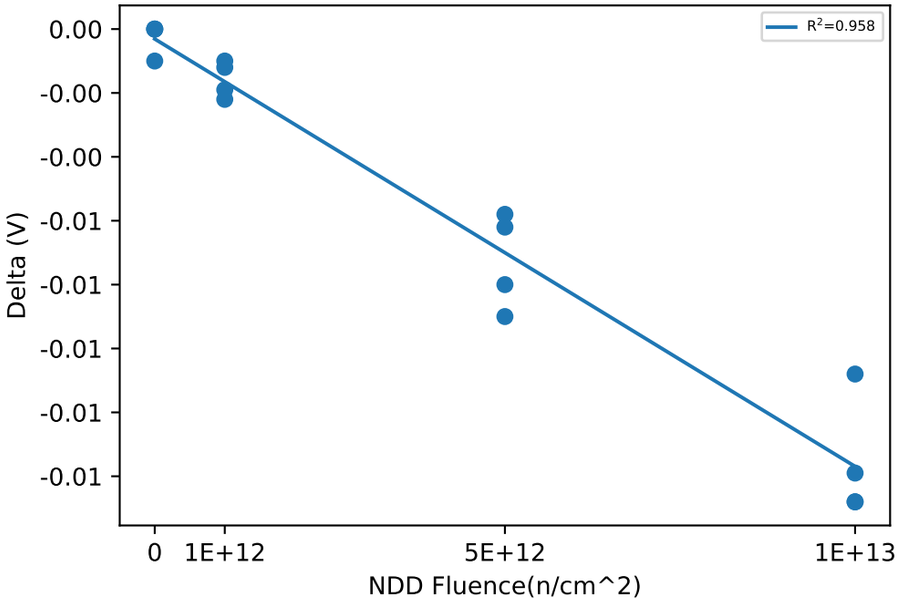
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7489	3.7625	3.7711	0.010327	3.7501	3.7633	3.7721	0.010016	0	0.000775	0.0012	0.00053151
1e+12	3.7591	3.7635	3.768	0.0041684	3.7578	3.762	3.7659	0.0040927	-0.0021	-0.001525	-0.0009	0.00053151
5e+12	3.752	3.7617	3.768	0.0069452	3.7461	3.7548	3.7609	0.0062554	-0.0081	-0.006975	-0.0059	0.00090692
1e+13	3.7578	3.7634	3.769	0.0050073	3.7421	3.749	3.7551	0.0070245	-0.017	-0.01435	-0.0108	0.0026864

Device Test: 17.2 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/100kHz//@PVIN_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

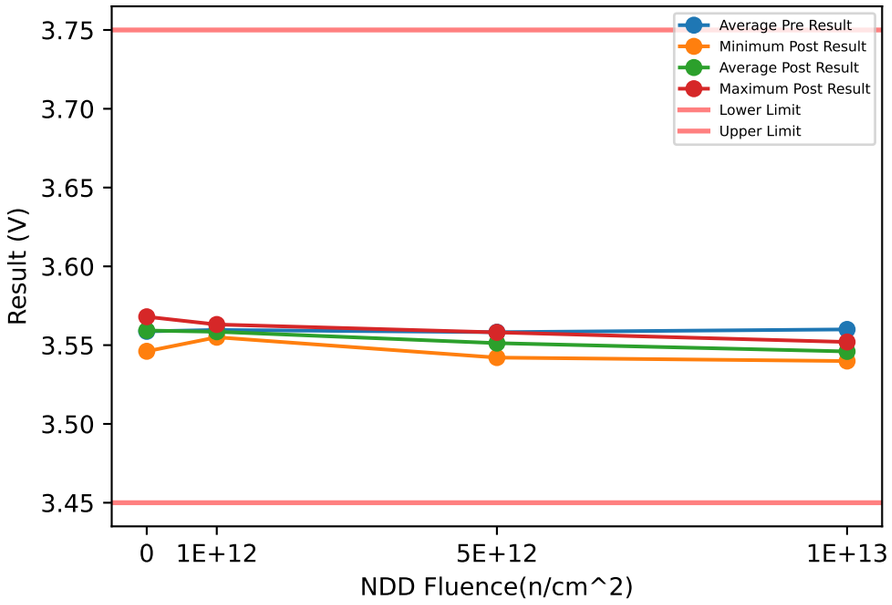
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.5699	3.5699	0
466	1e+12	NDD	3.5671	3.5649	-0.0022
762	0	CORRELATION	3.56	3.56	0
769	1e+12	NDD	3.5659	3.564	-0.0019
887	1e+12	NDD	3.5591	3.5581	-0.001
891	0	CORRELATION	3.569	3.568	-0.001
927	1e+12	NDD	3.5581	3.5569	-0.0012
967	5e+12	NDD	3.551	3.5452	-0.0058
1204	1e+13	NDD	3.5569	3.5421	-0.0148
1284	1e+13	NDD	3.5649	3.5541	-0.0108
1292	5e+12	NDD	3.5671	3.5609	-0.0062
1364	1e+13	NDD	3.568	3.5541	-0.0139
1383	5e+12	NDD	3.564	3.555	-0.009
1388	5e+12	NDD	3.5609	3.5529	-0.008
1427	1e+13	NDD	3.56	3.5452	-0.0148
1666	0	CORRELATION	3.5501	3.5501	0

Test Statistics (V)

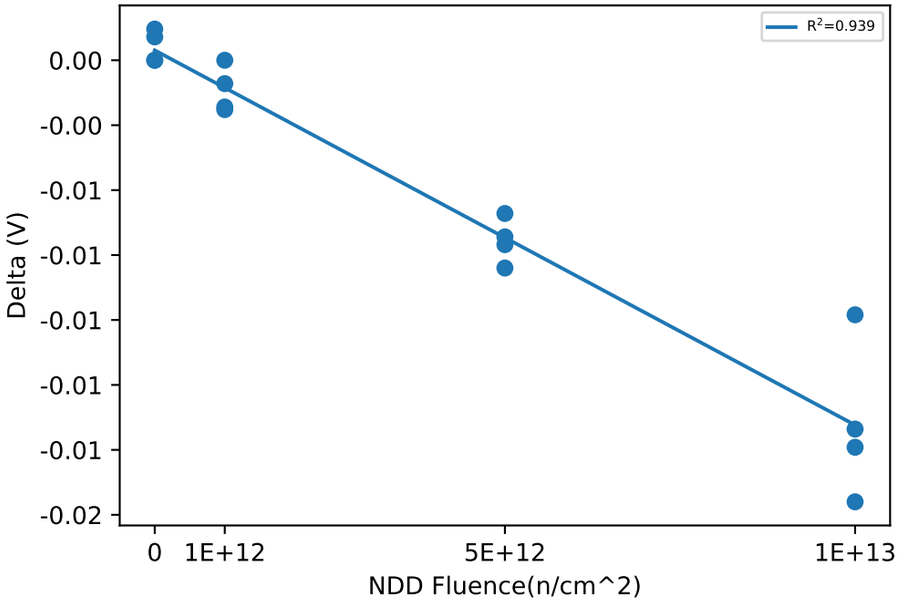
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5501	3.5623	3.5699	0.0092515	3.5501	3.562	3.5699	0.0090189	-0.001	-0.00025	0	0.0005
1e+12	3.5581	3.5625	3.5671	0.0046054	3.5569	3.561	3.5649	0.004059	-0.0022	-0.001575	-0.001	0.00056789
5e+12	3.551	3.5608	3.5671	0.0069754	3.5452	3.5535	3.5609	0.0064874	-0.009	-0.00725	-0.0058	0.0015089
1e+13	3.5569	3.5625	3.568	0.0049534	3.5421	3.5489	3.5541	0.0061646	-0.0148	-0.013575	-0.0108	0.001898

Device Test: 17.20 UVLO|PVIN_FALL/PVIN/4.5/4.5/0/1000/4.5/1MHz//@PVIN_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

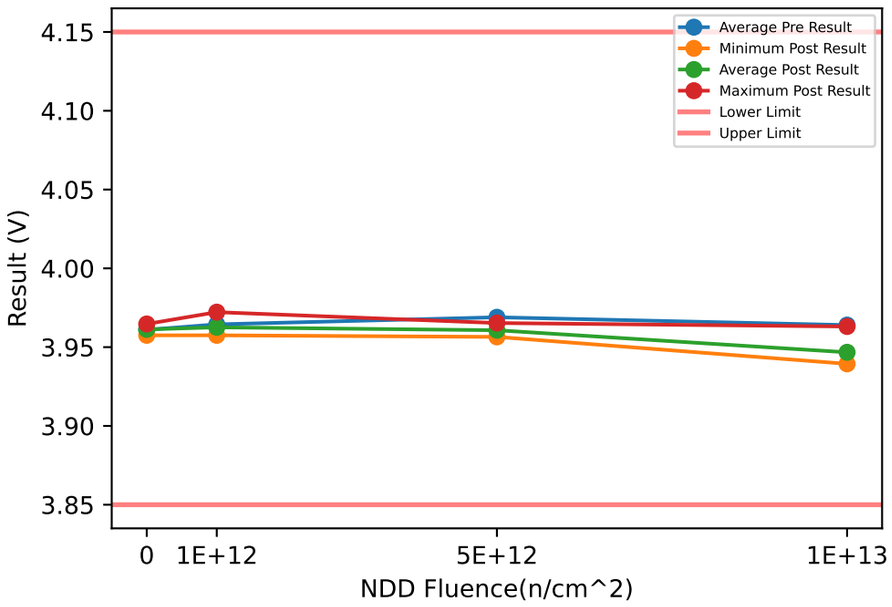
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.5671	3.568	0.0009
466	1e+12	NDD	3.5649	3.5631	-0.0018
762	0	CORRELATION	3.5569	3.5581	0.0012
769	1e+12	NDD	3.5618	3.5609	-0.0009
887	1e+12	NDD	3.5569	3.555	-0.0019
891	0	CORRELATION	3.5649	3.5649	0
927	1e+12	NDD	3.555	3.555	0
967	5e+12	NDD	3.5489	3.5421	-0.0068
1204	1e+13	NDD	3.5541	3.5399	-0.0142
1284	1e+13	NDD	3.5618	3.552	-0.0098
1292	5e+12	NDD	3.564	3.5581	-0.0059
1364	1e+13	NDD	3.5659	3.551	-0.0149
1383	5e+12	NDD	3.5609	3.5529	-0.008
1388	5e+12	NDD	3.5591	3.552	-0.0071
1427	1e+13	NDD	3.5581	3.5411	-0.017
1666	0	CORRELATION	3.5461	3.5461	0

Test Statistics (V)

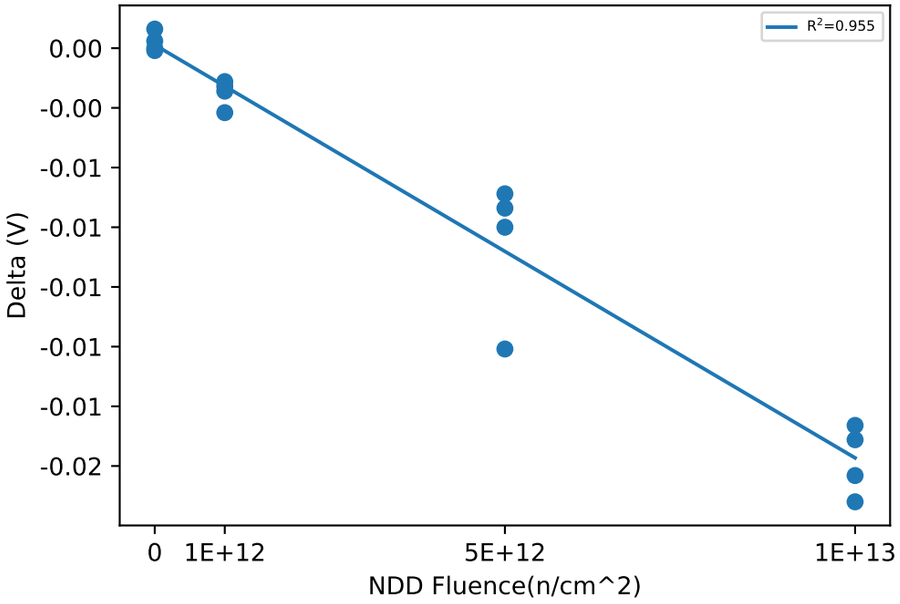
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5461	3.5587	3.5671	0.0095042	3.5461	3.5593	3.568	0.0097079	0	0.000525	0.0012	0.00061847
1e+12	3.555	3.5596	3.5649	0.0045229	3.555	3.5585	3.5631	0.00414	-0.0019	-0.00115	0	0.00088882
5e+12	3.5489	3.5582	3.564	0.0065378	3.5421	3.5513	3.5581	0.0066815	-0.008	-0.00695	-0.0059	0.00086603
1e+13	3.5541	3.56	3.5659	0.0050487	3.5399	3.546	3.552	0.0063828	-0.017	-0.013975	-0.0098	0.003027

Device Test: 17.22 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

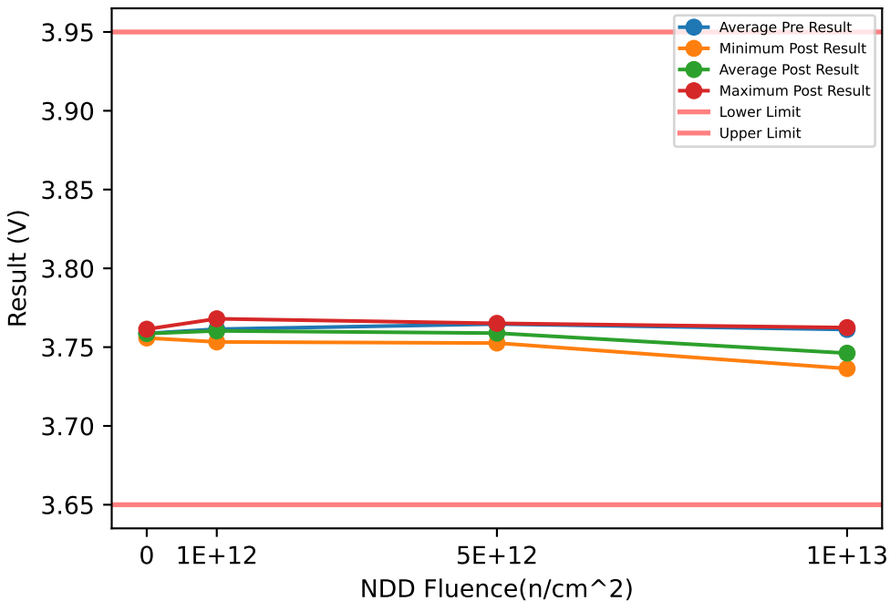
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.9631	3.9631	0
466	1e+12	NDD	3.9649	3.9622	-0.0027
762	0	CORRELATION	3.9576	3.9575	-0.0001
769	1e+12	NDD	3.9591	3.9575	-0.0016
887	1e+12	NDD	3.9736	3.9722	-0.0014
891	0	CORRELATION	3.9639	3.9647	0.0008
927	1e+12	NDD	3.9602	3.9584	-0.0018
967	5e+12	NDD	3.9716	3.959	-0.0126
1204	1e+13	NDD	3.9552	3.9394	-0.0158
1284	1e+13	NDD	3.9637	3.9447	-0.019
1292	5e+12	NDD	3.9714	3.9653	-0.0061
1364	1e+13	NDD	3.9576	3.9397	-0.0179
1383	5e+12	NDD	3.9632	3.9565	-0.0067
1388	5e+12	NDD	3.9696	3.9621	-0.0075
1427	1e+13	NDD	3.9795	3.9631	-0.0164
1666	0	CORRELATION	3.9594	3.9597	0.0003

Test Statistics (V)

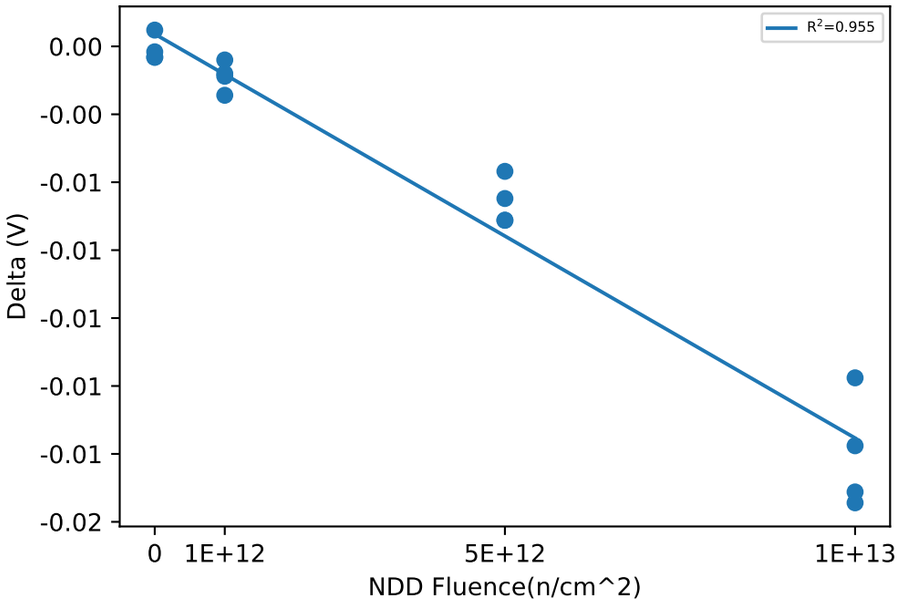
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9576	3.961	3.9639	0.0029967	3.9575	3.9613	3.9647	0.0032553	-0.0001	0.00025	0.0008	0.00040415
1e+12	3.9591	3.9644	3.9736	0.0065982	3.9575	3.9626	3.9722	0.0067322	-0.0027	-0.001875	-0.0014	0.00057373
5e+12	3.9632	3.9689	3.9716	0.0039374	3.9565	3.9607	3.9653	0.0038143	-0.0126	-0.008225	-0.0061	0.0029725
1e+13	3.9552	3.964	3.9795	0.010935	3.9394	3.9467	3.9631	0.011184	-0.019	-0.017275	-0.0158	0.00145

Device Test: 17.23 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/1MHz//@VIN_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

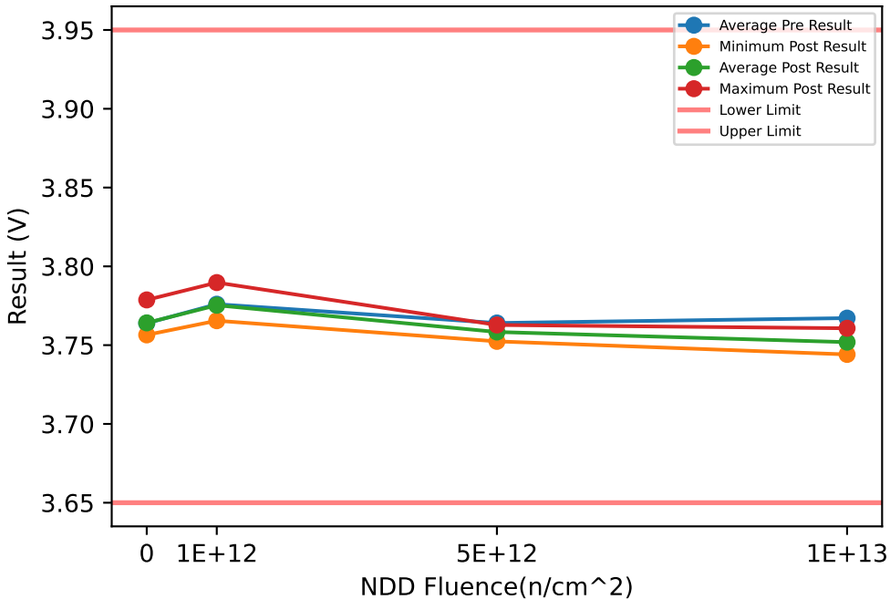
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7608	3.7614	0.0006
466	1e+12	NDD	3.762	3.7602	-0.0018
762	0	CORRELATION	3.7562	3.7558	-0.0004
769	1e+12	NDD	3.7538	3.7533	-0.0005
887	1e+12	NDD	3.769	3.768	-0.001
891	0	CORRELATION	3.7612	3.7608	-0.0004
927	1e+12	NDD	3.7609	3.7598	-0.0011
967	5e+12	NDD	3.7635	3.7571	-0.0064
1204	1e+13	NDD	3.7528	3.7364	-0.0164
1284	1e+13	NDD	3.7561	3.7439	-0.0122
1292	5e+12	NDD	3.7697	3.7651	-0.0046
1364	1e+13	NDD	3.7588	3.742	-0.0168
1383	5e+12	NDD	3.759	3.7526	-0.0064
1388	5e+12	NDD	3.7664	3.7608	-0.0056
1427	1e+13	NDD	3.7771	3.7624	-0.0147
1666	0	CORRELATION	3.7566	3.7564	-0.0002

Test Statistics (V)

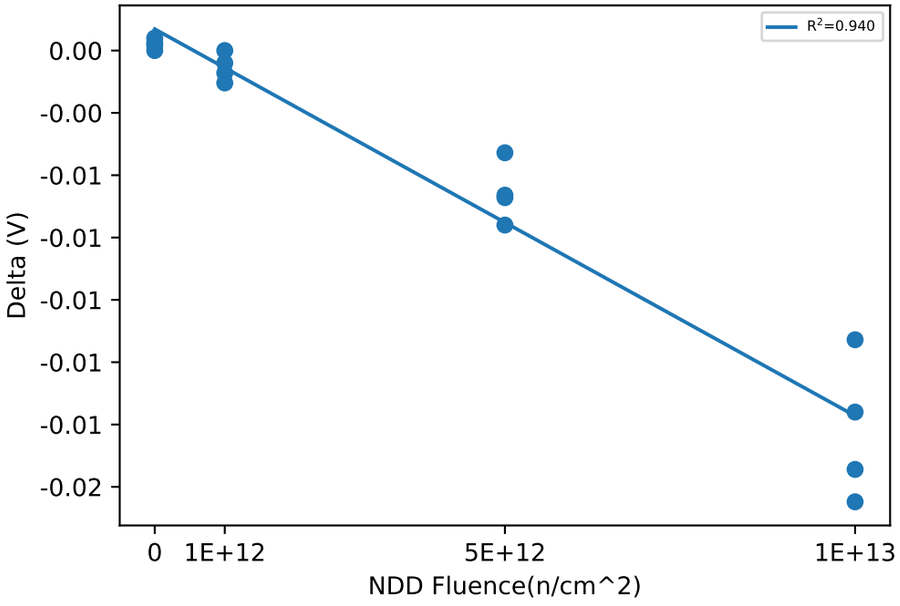
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7562	3.7587	3.7612	0.0026658	3.7558	3.7586	3.7614	0.0029075	-0.0004	-0.0001	0.0006	0.0004761
1e+12	3.7538	3.7614	3.769	0.0062217	3.7533	3.7603	3.768	0.0060152	-0.0018	-0.0011	-0.0005	0.00053541
5e+12	3.759	3.7647	3.7697	0.0045391	3.7526	3.7589	3.7651	0.0053223	-0.0064	-0.00575	-0.0046	0.0008544
1e+13	3.7528	3.7612	3.7771	0.01088	3.7364	3.7462	3.7624	0.011275	-0.0168	-0.015025	-0.0122	0.0020918

Device Test: 17.25 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/1MHz//@VLDO_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

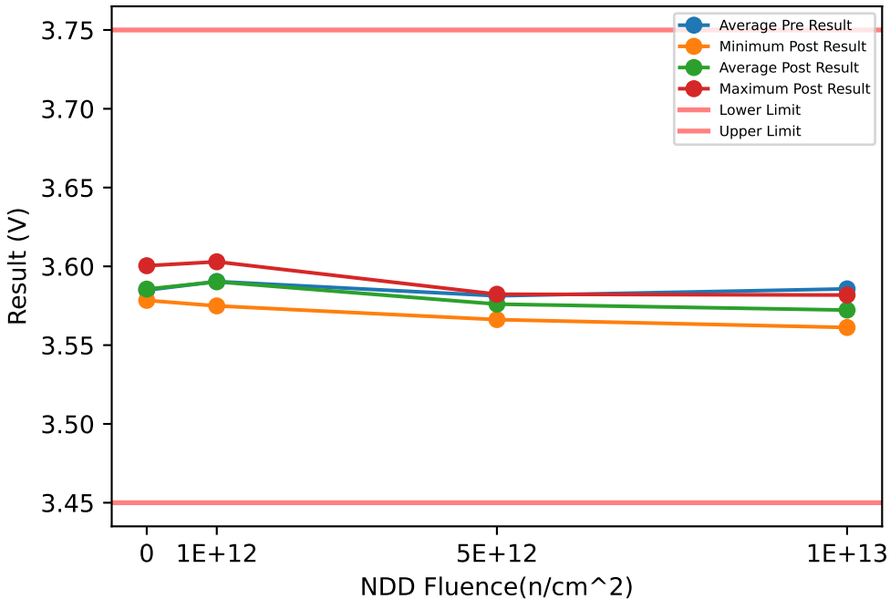
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7782	3.7787	0.0005
466	1e+12	NDD	3.7664	3.7655	-0.0009
762	0	CORRELATION	3.761	3.7612	0.0002
769	1e+12	NDD	3.7715	3.7715	0
887	1e+12	NDD	3.775	3.7745	-0.0005
891	0	CORRELATION	3.7601	3.7601	0
927	1e+12	NDD	3.791	3.7897	-0.0013
967	5e+12	NDD	3.7594	3.7524	-0.007
1204	1e+13	NDD	3.7685	3.7504	-0.0181
1284	1e+13	NDD	3.7723	3.7607	-0.0116
1292	5e+12	NDD	3.7657	3.7616	-0.0041
1364	1e+13	NDD	3.7609	3.7441	-0.0168
1383	5e+12	NDD	3.7625	3.7566	-0.0059
1388	5e+12	NDD	3.7686	3.7628	-0.0058
1427	1e+13	NDD	3.7669	3.7524	-0.0145
1666	0	CORRELATION	3.7562	3.7565	0.0003

Test Statistics (V)

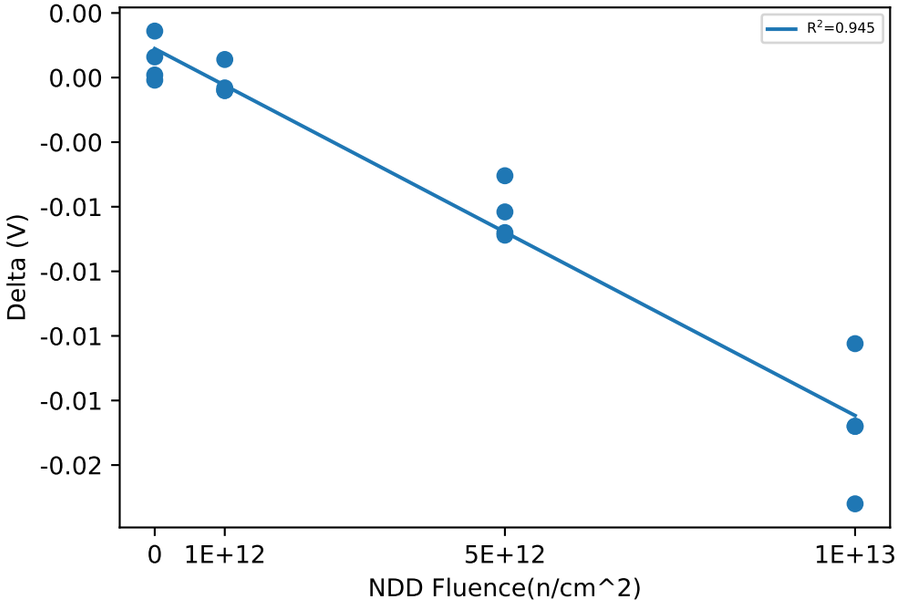
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7562	3.7639	3.7782	0.0097746	3.7565	3.7641	3.7787	0.0099218	0	0.00025	0.0005	0.00020817
1e+12	3.7664	3.776	3.791	0.010621	3.7655	3.7753	3.7897	0.010303	-0.0013	-0.000675	0	0.00055603
5e+12	3.7594	3.7641	3.7686	0.003977	3.7524	3.7584	3.7628	0.0047899	-0.007	-0.0057	-0.0041	0.0011972
1e+13	3.7609	3.7671	3.7723	0.0047424	3.7441	3.7519	3.7607	0.0068503	-0.0181	-0.01525	-0.0116	0.0028525

Device Test: 17.26 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/1MHz//@VLDO_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

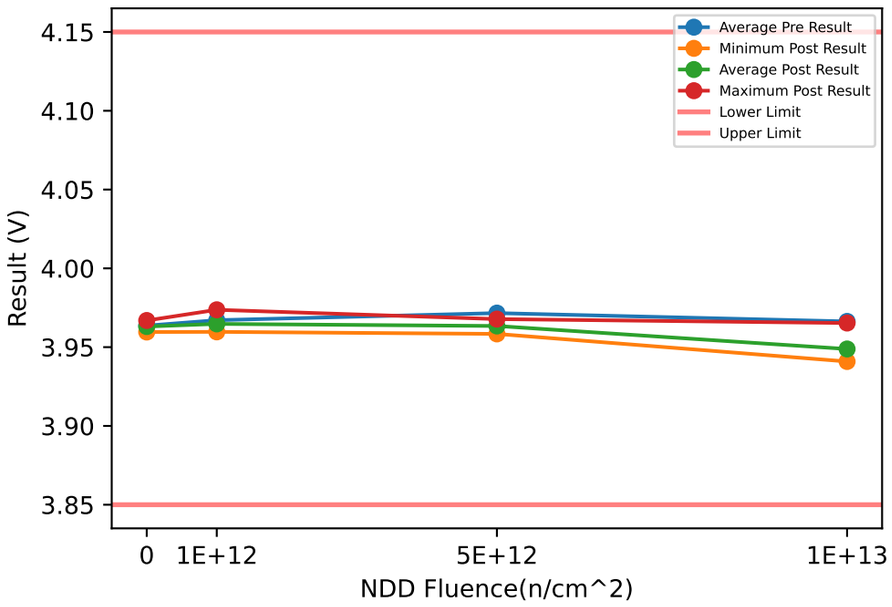
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.6003	3.6004	0.0001
466	1e+12	NDD	3.5753	3.5749	-0.0004
762	0	CORRELATION	3.5789	3.5788	-0.0001
769	1e+12	NDD	3.5917	3.5912	-0.0005
887	1e+12	NDD	3.5911	3.5918	0.0007
891	0	CORRELATION	3.5828	3.5846	0.0018
927	1e+12	NDD	3.6034	3.6029	-0.0005
967	5e+12	NDD	3.5714	3.5662	-0.0052
1204	1e+13	NDD	3.5822	3.5687	-0.0135
1284	1e+13	NDD	3.5921	3.5818	-0.0103
1292	5e+12	NDD	3.579	3.5752	-0.0038
1364	1e+13	NDD	3.5908	3.5773	-0.0135
1383	5e+12	NDD	3.5883	3.5823	-0.006
1388	5e+12	NDD	3.5865	3.5804	-0.0061
1427	1e+13	NDD	3.5777	3.5612	-0.0165
1666	0	CORRELATION	3.5776	3.5784	0.0008

Test Statistics (V)

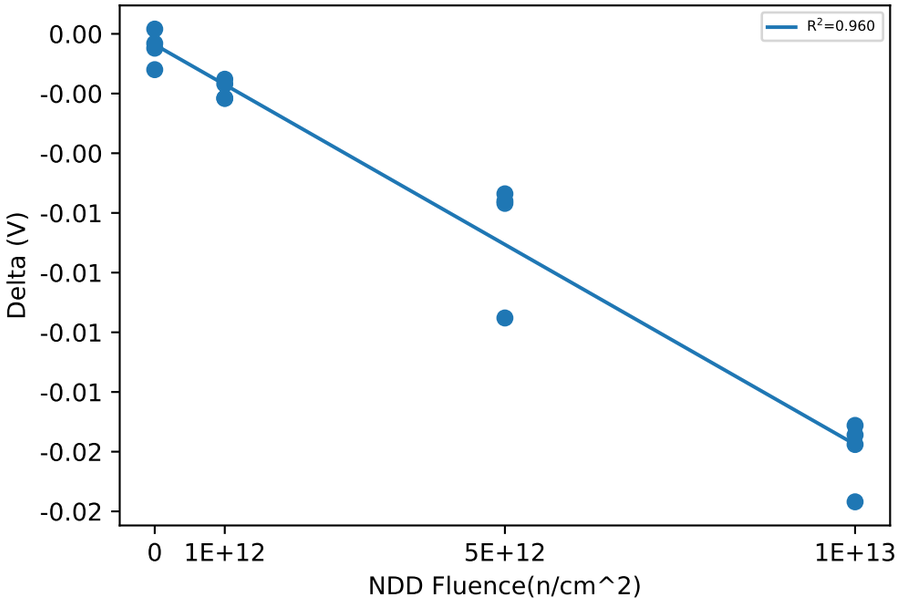
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5776	3.5849	3.6003	0.010502	3.5784	3.5856	3.6004	0.010297	-0.0001	0.00065	0.0018	0.00085829
1e+12	3.5753	3.5904	3.6034	0.011535	3.5749	3.5902	3.6029	0.011532	-0.0005	-0.000175	0.0007	0.00058523
5e+12	3.5714	3.5813	3.5883	0.0077318	3.5662	3.576	3.5823	0.0072048	-0.0061	-0.005275	-0.0038	0.0010626
1e+13	3.5777	3.5857	3.5921	0.0069094	3.5612	3.5722	3.5818	0.0091544	-0.0165	-0.01345	-0.0103	0.0025318

Device Test: 17.4 UVLO|VIN_RISE/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.85, Upper Limit = 4.15 (V))

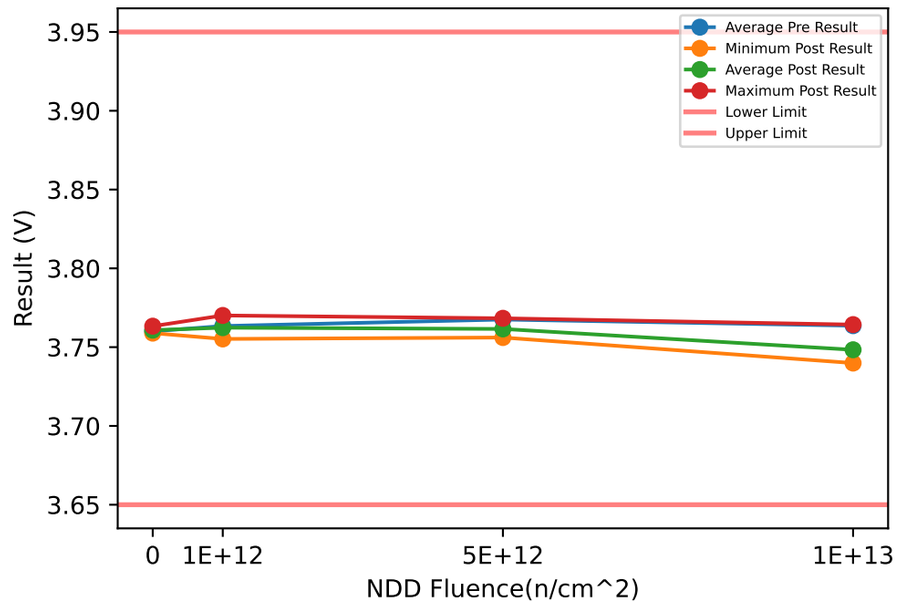
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.9649	3.9643	-0.0006
466	1e+12	NDD	3.9674	3.9647	-0.0027
762	0	CORRELATION	3.9611	3.9596	-0.0015
769	1e+12	NDD	3.9616	3.9597	-0.0019
887	1e+12	NDD	3.9764	3.9737	-0.0027
891	0	CORRELATION	3.9667	3.9669	0.0002
927	1e+12	NDD	3.963	3.9609	-0.0021
967	5e+12	NDD	3.9741	3.9622	-0.0119
1204	1e+13	NDD	3.9577	3.9409	-0.0168
1284	1e+13	NDD	3.9665	3.9469	-0.0196
1292	5e+12	NDD	3.9745	3.9678	-0.0067
1364	1e+13	NDD	3.9594	3.9422	-0.0172
1383	5e+12	NDD	3.9654	3.9584	-0.007
1388	5e+12	NDD	3.9724	3.9653	-0.0071
1427	1e+13	NDD	3.9817	3.9653	-0.0164
1666	0	CORRELATION	3.9619	3.9615	-0.0004

Test Statistics (V)

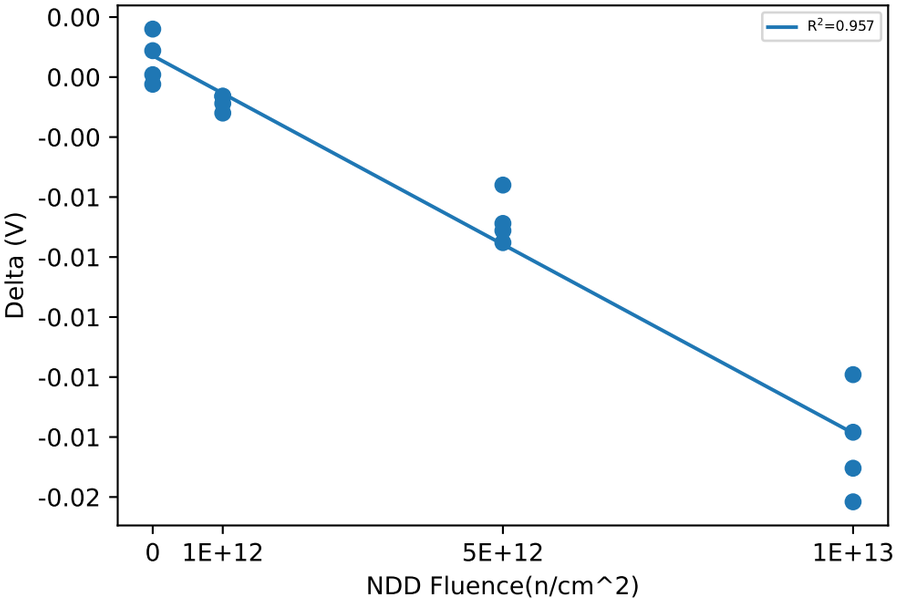
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9611	3.9636	3.9667	0.0026096	3.9596	3.9631	3.9669	0.0031983	-0.0015	-0.000575	0.0002	0.00070415
1e+12	3.9616	3.9671	3.9764	0.0066743	3.9597	3.9647	3.9737	0.0063359	-0.0027	-0.00235	-0.0019	0.00041231
5e+12	3.9654	3.9716	3.9745	0.0042324	3.9584	3.9634	3.9678	0.0040582	-0.0119	-0.008175	-0.0067	0.0024891
1e+13	3.9577	3.9663	3.9817	0.010936	3.9409	3.9488	3.9653	0.011282	-0.0196	-0.0175	-0.0164	0.0014376

Device Test: 17.5 UVLO|VIN_FALL/VIN/4.5/4.5/0/1000/4.5/100kHz//@VIN_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

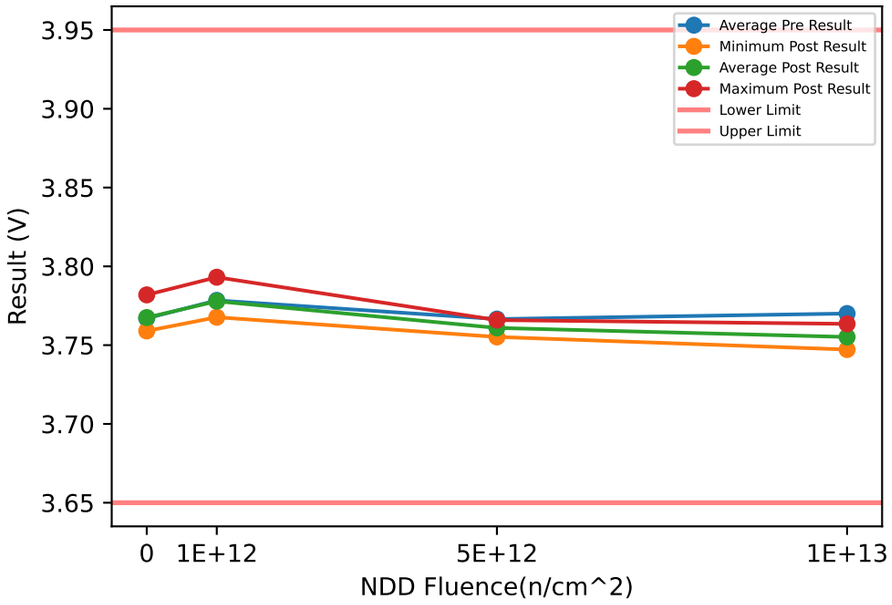
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7636	3.7633	-0.0003
466	1e+12	NDD	3.7645	3.763	-0.0015
762	0	CORRELATION	3.7578	3.7589	0.0011
769	1e+12	NDD	3.7563	3.7552	-0.0011
887	1e+12	NDD	3.7709	3.7701	-0.0008
891	0	CORRELATION	3.76	3.7601	0.0001
927	1e+12	NDD	3.7619	3.7611	-0.0008
967	5e+12	NDD	3.7653	3.7589	-0.0064
1204	1e+13	NDD	3.7547	3.7399	-0.0148
1284	1e+13	NDD	3.7576	3.7452	-0.0124
1292	5e+12	NDD	3.7728	3.7683	-0.0045
1364	1e+13	NDD	3.7616	3.7439	-0.0177
1383	5e+12	NDD	3.7622	3.7561	-0.0061
1388	5e+12	NDD	3.7698	3.7629	-0.0069
1427	1e+13	NDD	3.7806	3.7643	-0.0163
1666	0	CORRELATION	3.7588	3.7608	0.002

Test Statistics (V)

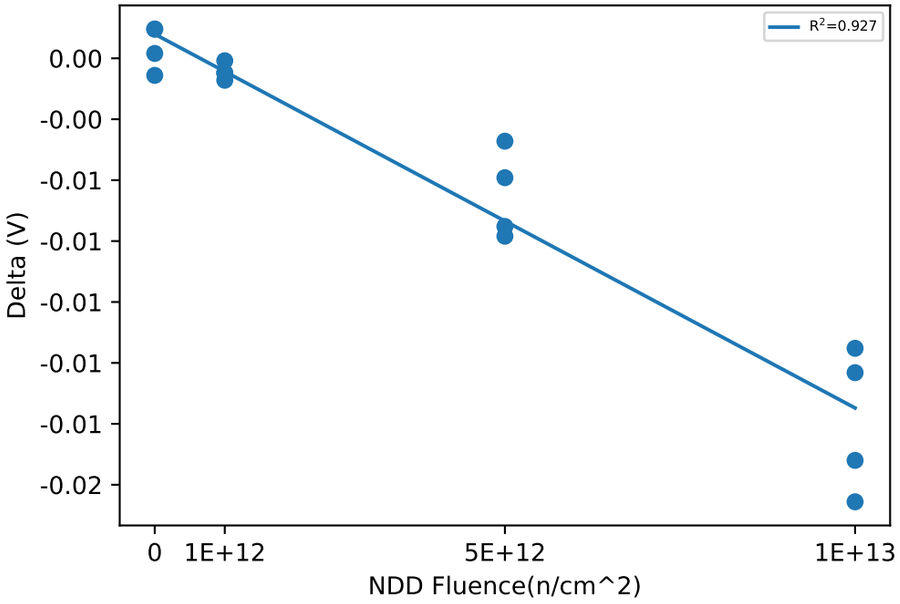
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7578	3.76	3.7636	0.0025318	3.7589	3.7608	3.7633	0.0018572	-0.0003	0.000725	0.002	0.001034
1e+12	3.7563	3.7634	3.7709	0.0060586	3.7552	3.7623	3.7701	0.0061419	-0.0015	-0.00105	-0.0008	0.00033166
5e+12	3.7622	3.7675	3.7728	0.0047013	3.7561	3.7616	3.7683	0.005295	-0.0069	-0.005975	-0.0045	0.0010372
1e+13	3.7547	3.7636	3.7806	0.011665	3.7399	3.7483	3.7643	0.010886	-0.0177	-0.0153	-0.0124	0.0022672

Device Test: 17.7 UVLO|VLDO_RISE/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_RISE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.65, Upper Limit = 3.95 (V))

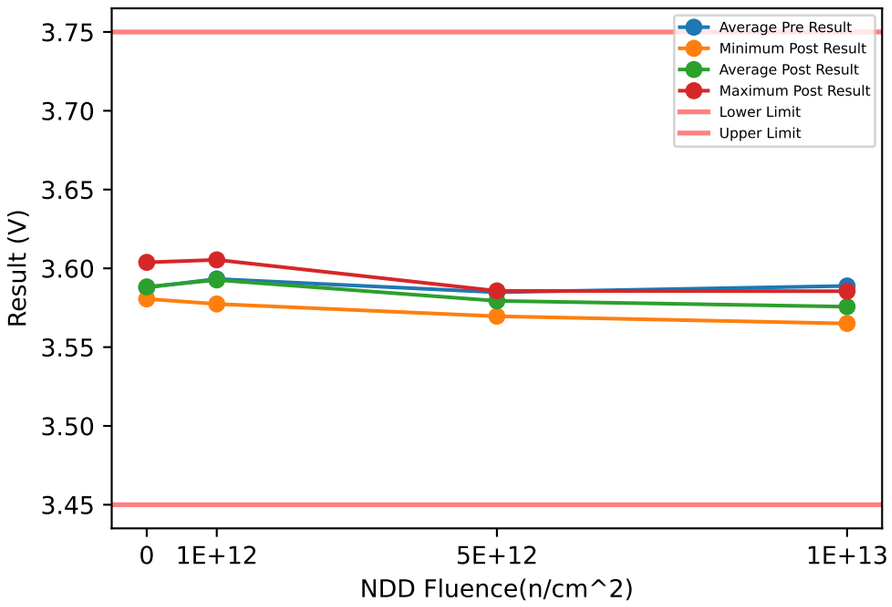
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.7807	3.7819	0.0012
466	1e+12	NDD	3.7686	3.7677	-0.0009
762	0	CORRELATION	3.7641	3.7653	0.0012
769	1e+12	NDD	3.7746	3.774	-0.0006
887	1e+12	NDD	3.7772	3.7766	-0.0006
891	0	CORRELATION	3.7636	3.7638	0.0002
927	1e+12	NDD	3.7932	3.7931	-0.0001
967	5e+12	NDD	3.7625	3.7552	-0.0073
1204	1e+13	NDD	3.7717	3.7535	-0.0182
1284	1e+13	NDD	3.7754	3.7635	-0.0119
1292	5e+12	NDD	3.7682	3.7648	-0.0034
1364	1e+13	NDD	3.7637	3.7472	-0.0165
1383	5e+12	NDD	3.7647	3.7578	-0.0069
1388	5e+12	NDD	3.7708	3.7659	-0.0049
1427	1e+13	NDD	3.7694	3.7565	-0.0129
1666	0	CORRELATION	3.7597	3.759	-0.0007

Test Statistics (V)

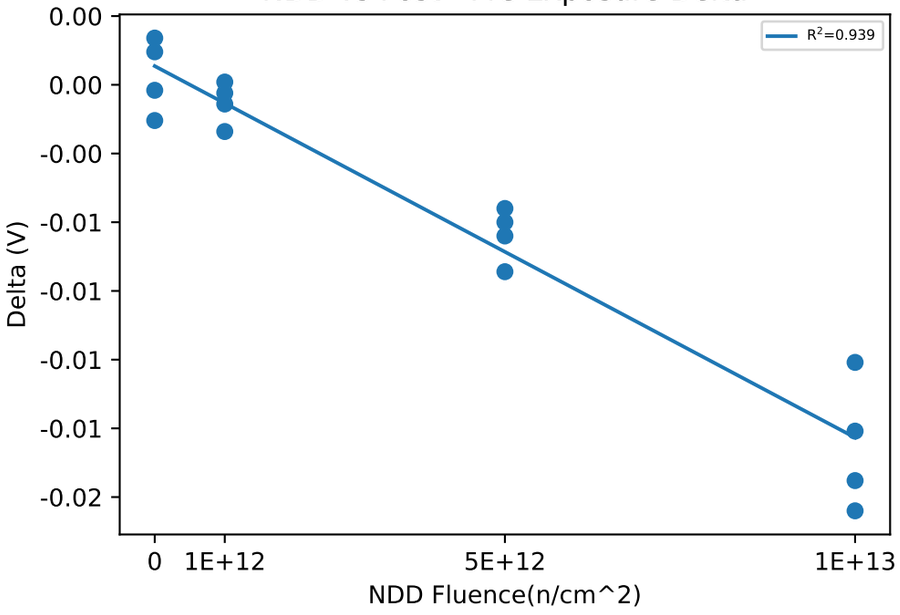
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.7597	3.767	3.7807	0.0093264	3.759	3.7675	3.7819	0.009969	-0.0007	0.000475	0.0012	0.00091424
1e+12	3.7686	3.7784	3.7932	0.010503	3.7677	3.7778	3.7931	0.010832	-0.0009	-0.00055	-0.0001	0.00033166
5e+12	3.7625	3.7666	3.7708	0.0036792	3.7552	3.7609	3.7659	0.0052379	-0.0073	-0.005625	-0.0034	0.0018173
1e+13	3.7637	3.77	3.7754	0.004902	3.7472	3.7552	3.7635	0.0067692	-0.0182	-0.014875	-0.0119	0.0029691

Device Test: 17.8 UVLO|VLDO_FALL/VLDO/4.5/4.5/0/1000/4.5/100kHz//@VLDO_UVLO_FALL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 3.45, Upper Limit = 3.75 (V))

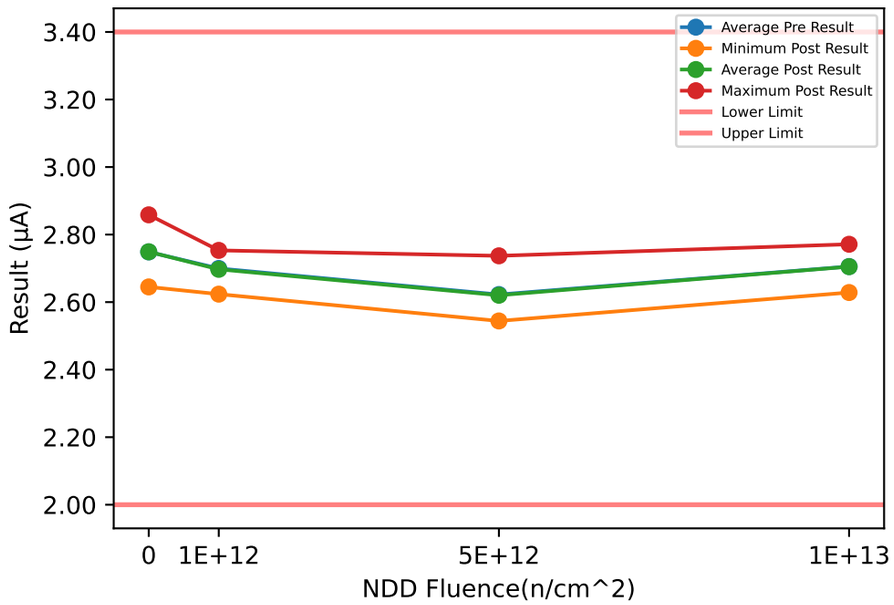
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.6021	3.6038	0.0017
466	1e+12	NDD	3.5781	3.5774	-0.0007
762	0	CORRELATION	3.5811	3.5823	0.0012
769	1e+12	NDD	3.5951	3.5934	-0.0017
887	1e+12	NDD	3.5946	3.5943	-0.0003
891	0	CORRELATION	3.5875	3.5862	-0.0013
927	1e+12	NDD	3.6053	3.6054	0.0001
967	5e+12	NDD	3.5751	3.5696	-0.0055
1204	1e+13	NDD	3.5859	3.5715	-0.0144
1284	1e+13	NDD	3.5956	3.5855	-0.0101
1292	5e+12	NDD	3.5837	3.5787	-0.005
1364	1e+13	NDD	3.5933	3.5807	-0.0126
1383	5e+12	NDD	3.5902	3.5857	-0.0045
1388	5e+12	NDD	3.5903	3.5835	-0.0068
1427	1e+13	NDD	3.5805	3.565	-0.0155
1666	0	CORRELATION	3.5808	3.5806	-0.0002

Test Statistics (V)

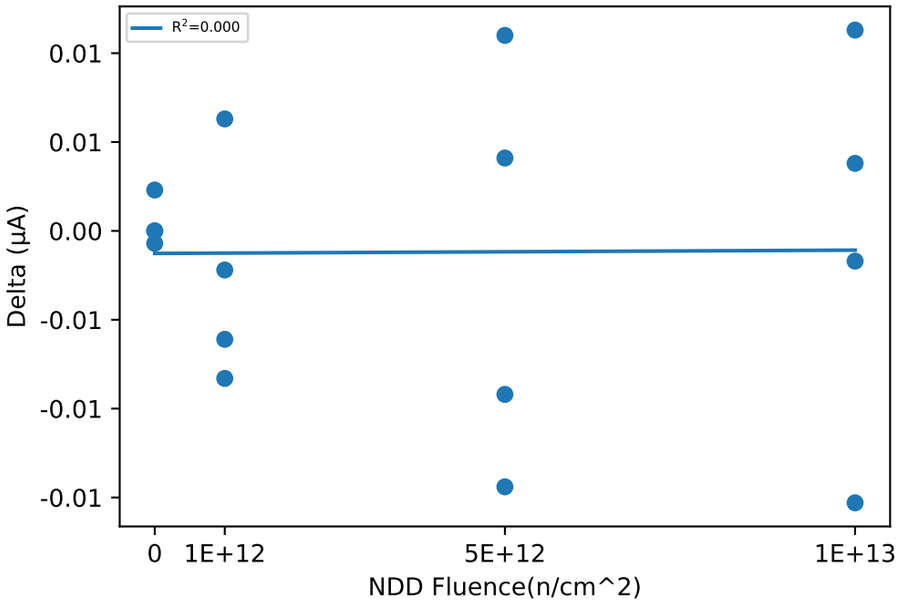
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.5808	3.5879	3.6021	0.0099741	3.5806	3.5882	3.6038	0.010645	-0.0013	0.00035	0.0017	0.0013626
1e+12	3.5781	3.5933	3.6053	0.011254	3.5774	3.5926	3.6054	0.011524	-0.0017	-0.00065	0.0001	0.00077244
5e+12	3.5751	3.5848	3.5903	0.0071812	3.5696	3.5794	3.5857	0.0071421	-0.0068	-0.00545	-0.0045	0.00098826
1e+13	3.5805	3.5888	3.5956	0.0069231	3.565	3.5757	3.5855	0.0091864	-0.0155	-0.01315	-0.0101	0.0023587

Device Test: 18.1 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/100kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

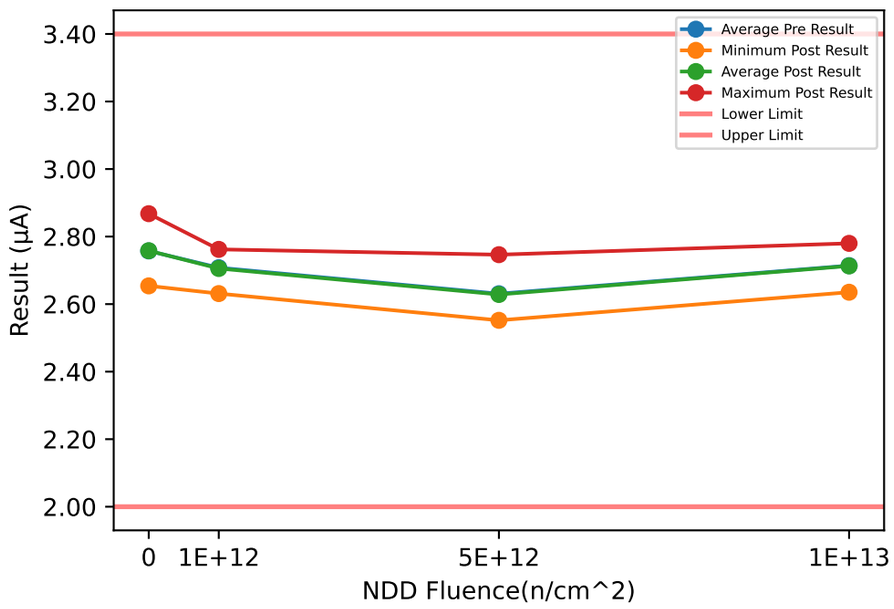
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7505	2.7505	0
466	1e+12	NDD	2.7469	2.7532	0.0063
762	0	CORRELATION	2.8562	2.8585	0.0023
769	1e+12	NDD	2.6258	2.6236	-0.0022
887	1e+12	NDD	2.6805	2.6744	-0.0061
891	0	CORRELATION	2.7423	2.7423	0
927	1e+12	NDD	2.7456	2.7373	-0.0083
967	5e+12	NDD	2.6387	2.6295	-0.0092
1204	1e+13	NDD	2.662	2.6603	-0.0017
1284	1e+13	NDD	2.6437	2.6284	-0.0153
1292	5e+12	NDD	2.7515	2.7371	-0.0144
1364	1e+13	NDD	2.7675	2.7713	0.0038
1383	5e+12	NDD	2.5401	2.5442	0.0041
1388	5e+12	NDD	2.5595	2.5705	0.011
1427	1e+13	NDD	2.7486	2.7599	0.0113
1666	0	CORRELATION	2.6457	2.645	-0.0007

Test Statistics (µA)

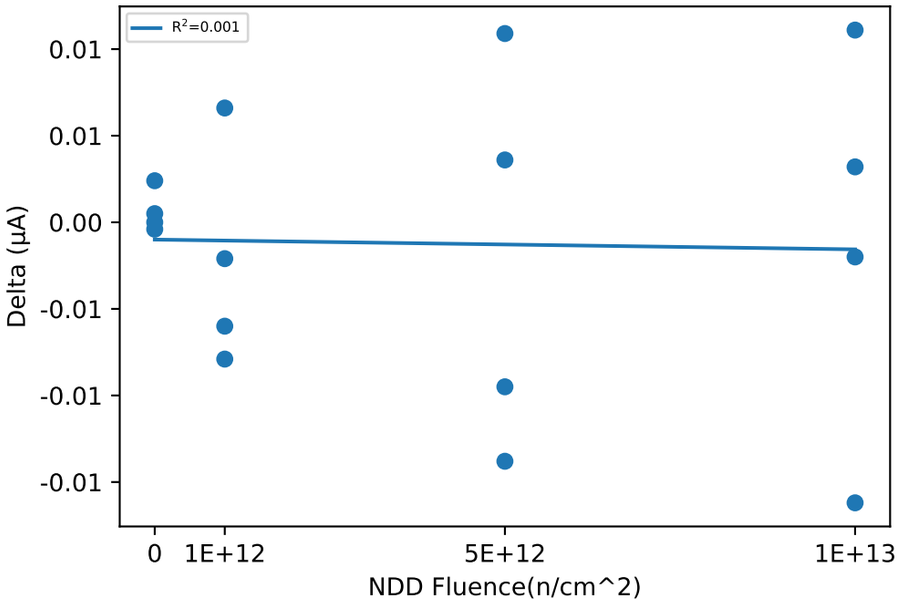
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6457	2.7487	2.8562	0.086042	2.645	2.7491	2.8585	0.08728	-0.0007	0.0004	0.0023	0.0013089
1e+12	2.6258	2.6997	2.7469	0.058208	2.6236	2.6971	2.7532	0.059668	-0.0083	-0.002575	0.0063	0.0064319
5e+12	2.5401	2.6224	2.7515	0.096025	2.5442	2.6203	2.7371	0.085631	-0.0144	-0.002125	0.011	0.011715
1e+13	2.6437	2.7054	2.7675	0.06168	2.6284	2.705	2.7713	0.071357	-0.0153	-0.000475	0.0113	0.011228

Device Test: 18.13 CURRENT|SS_0p3V/SS/14/14/0/1000/5/100kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

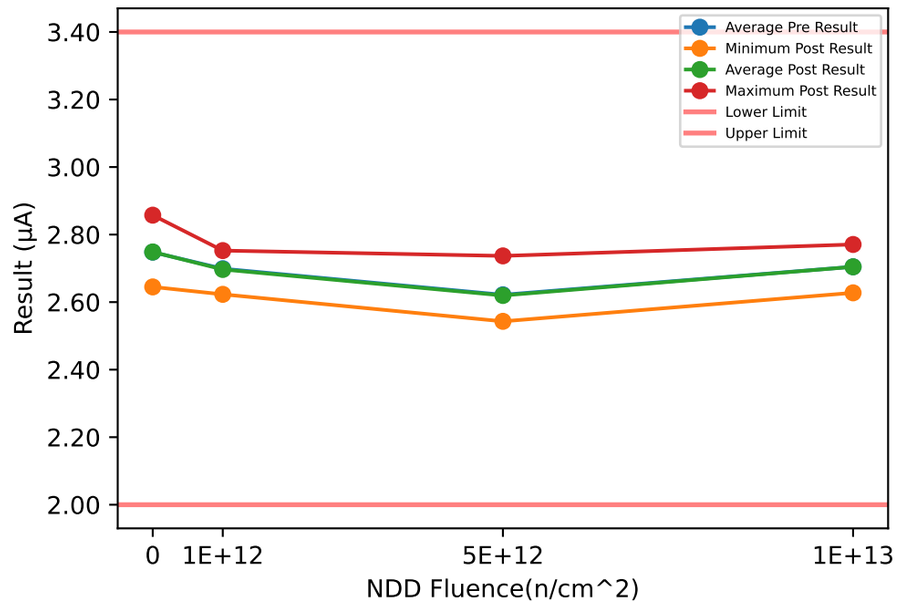
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7594	2.759	-0.0004
466	1e+12	NDD	2.7555	2.7621	0.0066
762	0	CORRELATION	2.8654	2.8678	0.0024
769	1e+12	NDD	2.6333	2.6312	-0.0021
887	1e+12	NDD	2.6886	2.6826	-0.006
891	0	CORRELATION	2.7511	2.7516	0.0005
927	1e+12	NDD	2.754	2.7461	-0.0079
967	5e+12	NDD	2.6468	2.6373	-0.0095
1204	1e+13	NDD	2.6708	2.6688	-0.002
1284	1e+13	NDD	2.6514	2.6352	-0.0162
1292	5e+12	NDD	2.7602	2.7464	-0.0138
1364	1e+13	NDD	2.7767	2.7799	0.0032
1383	5e+12	NDD	2.5484	2.552	0.0036
1388	5e+12	NDD	2.5675	2.5784	0.0109
1427	1e+13	NDD	2.7572	2.7683	0.0111
1666	0	CORRELATION	2.654	2.654	0

Test Statistics (µA)

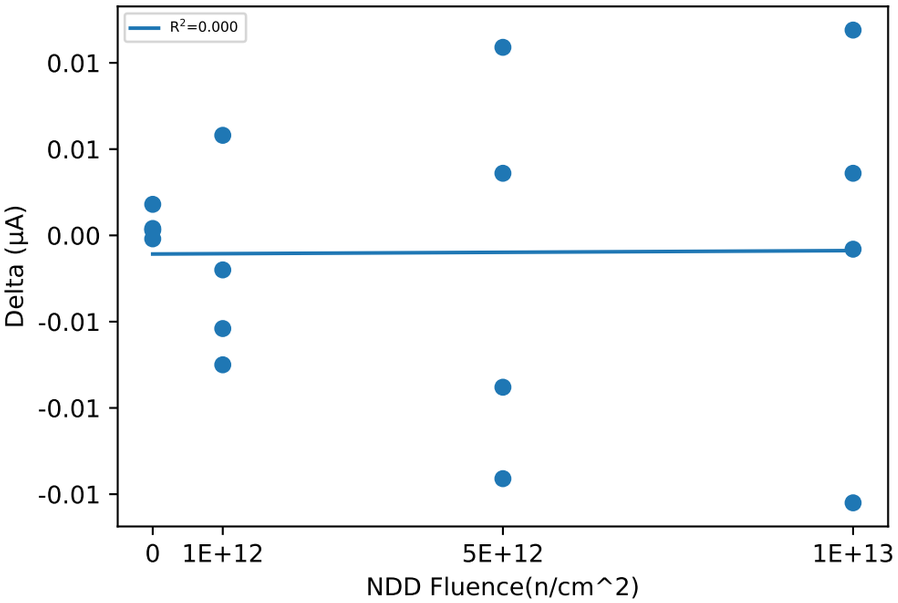
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.654	2.7575	2.8654	0.086408	2.654	2.7581	2.8678	0.087396	-0.0004	0.000625	0.0024	0.0012393
1e+12	2.6333	2.7079	2.7555	0.058676	2.6312	2.7055	2.7621	0.060268	-0.0079	-0.00235	0.0066	0.0064366
5e+12	2.5484	2.6307	2.7602	0.096258	2.552	2.6285	2.7464	0.086294	-0.0138	-0.0022	0.0109	0.011447
1e+13	2.6514	2.714	2.7767	0.062136	2.6352	2.713	2.7799	0.071973	-0.0162	-0.000975	0.0111	0.01149

Device Test: 18.17 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/500kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

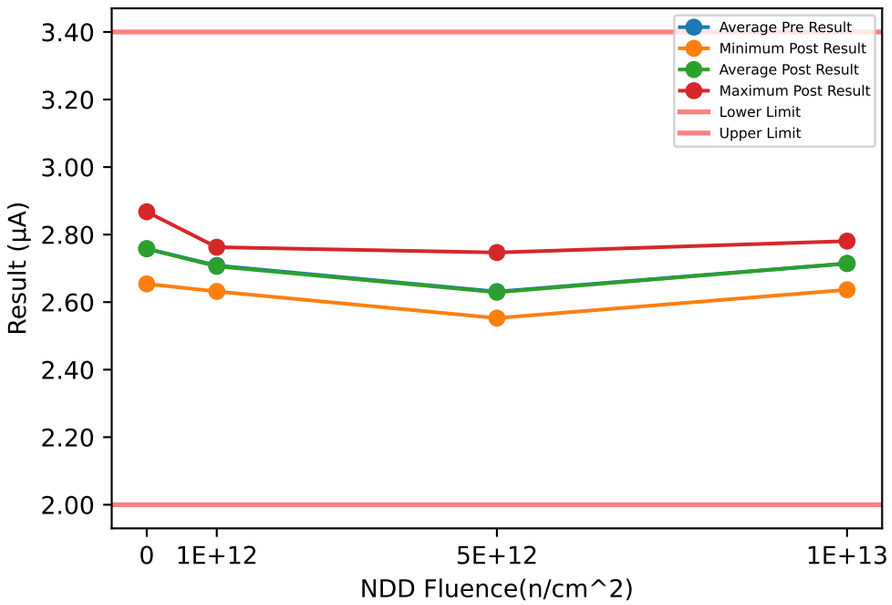
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7498	2.7496	-0.0002
466	1e+12	NDD	2.7468	2.7526	0.0058
762	0	CORRELATION	2.8557	2.8575	0.0018
769	1e+12	NDD	2.625	2.623	-0.002
887	1e+12	NDD	2.6797	2.6743	-0.0054
891	0	CORRELATION	2.7416	2.7419	0.0003
927	1e+12	NDD	2.7444	2.7369	-0.0075
967	5e+12	NDD	2.6378	2.629	-0.0088
1204	1e+13	NDD	2.6611	2.6603	-0.0008
1284	1e+13	NDD	2.643	2.6275	-0.0155
1292	5e+12	NDD	2.751	2.7369	-0.0141
1364	1e+13	NDD	2.7671	2.7707	0.0036
1383	5e+12	NDD	2.5395	2.5431	0.0036
1388	5e+12	NDD	2.5587	2.5696	0.0109
1427	1e+13	NDD	2.7476	2.7595	0.0119
1666	0	CORRELATION	2.6446	2.645	0.0004

Test Statistics (µA)

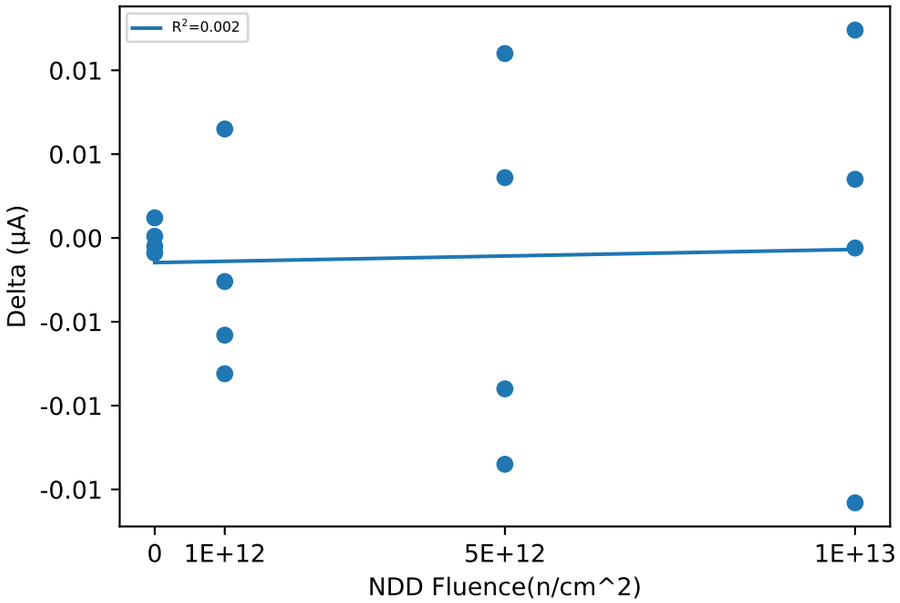
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6446	2.7479	2.8557	0.086284	2.645	2.7485	2.8575	0.086868	-0.0002	0.000575	0.0018	0.00085781
1e+12	2.625	2.699	2.7468	0.058294	2.623	2.6967	2.7526	0.05965	-0.0075	-0.002275	0.0058	0.0058409
5e+12	2.5395	2.6218	2.751	0.096096	2.5431	2.6197	2.7369	0.086023	-0.0141	-0.0021	0.0109	0.011407
1e+13	2.643	2.7047	2.7671	0.061758	2.6275	2.7045	2.7707	0.071391	-0.0155	-0.0002	0.0119	0.011479

Device Test: 18.21 CURRENT|SS_0p3V/SS/5/5/0/1000/5/500kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

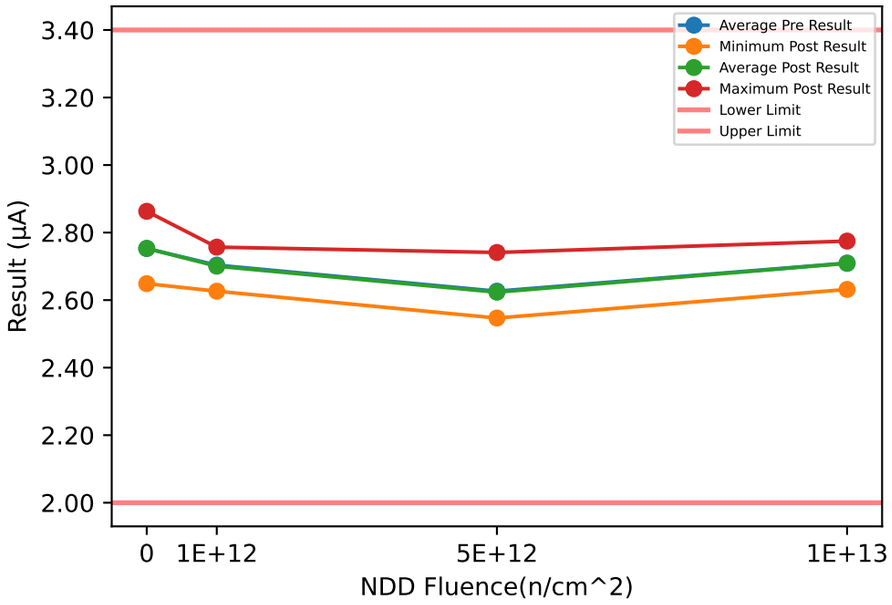
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7601	2.7596	-0.0005
466	1e+12	NDD	2.7561	2.7626	0.0065
762	0	CORRELATION	2.8663	2.8675	0.0012
769	1e+12	NDD	2.6342	2.6316	-0.0026
887	1e+12	NDD	2.6891	2.6833	-0.0058
891	0	CORRELATION	2.752	2.7511	-0.0009
927	1e+12	NDD	2.7544	2.7463	-0.0081
967	5e+12	NDD	2.647	2.638	-0.009
1204	1e+13	NDD	2.6708	2.6702	-0.0006
1284	1e+13	NDD	2.6523	2.6365	-0.0158
1292	5e+12	NDD	2.7604	2.7469	-0.0135
1364	1e+13	NDD	2.7772	2.7807	0.0035
1383	5e+12	NDD	2.5491	2.5527	0.0036
1388	5e+12	NDD	2.5678	2.5788	0.011
1427	1e+13	NDD	2.7575	2.7699	0.0124
1666	0	CORRELATION	2.654	2.6541	0.0001

Test Statistics (µA)

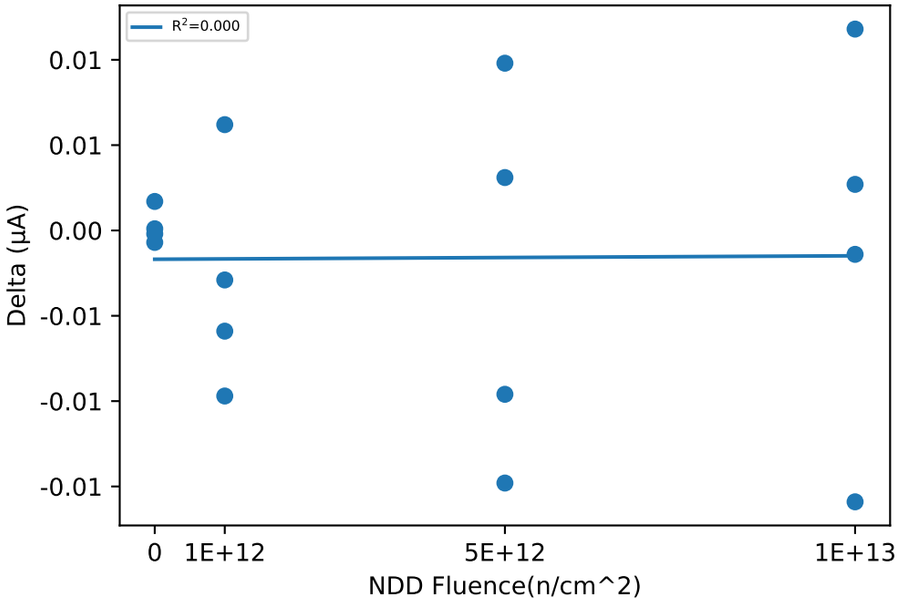
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.654	2.7581	2.8663	0.086766	2.6541	2.7581	2.8675	0.087246	-0.0009	-2.5e-05	0.0012	0.00091424
1e+12	2.6342	2.7085	2.7561	0.058508	2.6316	2.706	2.7626	0.060217	-0.0081	-0.0025	0.0065	0.0064099
5e+12	2.5491	2.6311	2.7604	0.096094	2.5527	2.6291	2.7469	0.086261	-0.0135	-0.001975	0.011	0.011278
1e+13	2.6523	2.7144	2.7772	0.062072	2.6365	2.7143	2.7807	0.071875	-0.0158	-0.000125	0.0124	0.011775

Device Test: 18.25 CURRENT|SS_0p3V/SS/12/12/0/1000/5/500kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

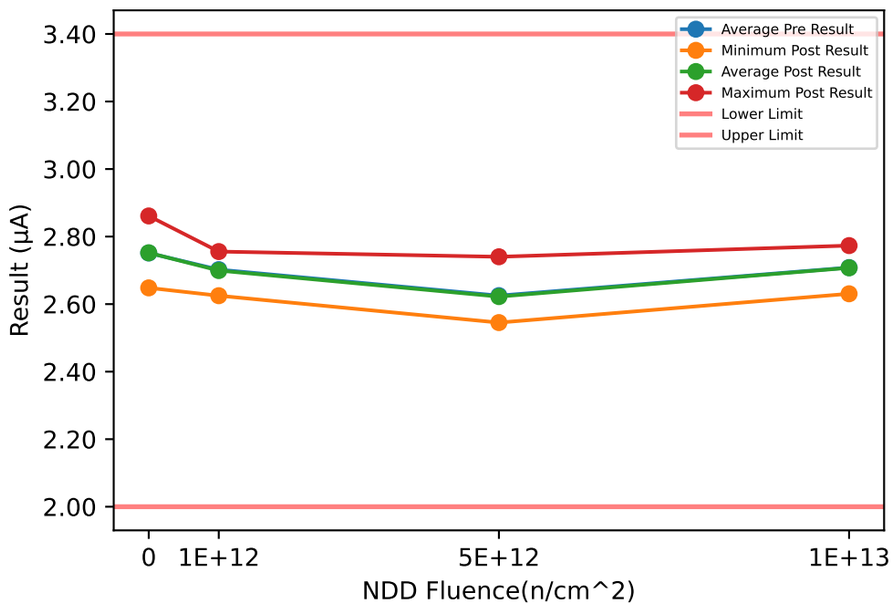
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7538	2.7539	0.0001
466	1e+12	NDD	2.7507	2.7569	0.0062
762	0	CORRELATION	2.8613	2.863	0.0017
769	1e+12	NDD	2.6293	2.6264	-0.0029
887	1e+12	NDD	2.684	2.6781	-0.0059
891	0	CORRELATION	2.7469	2.7467	-0.0002
927	1e+12	NDD	2.7503	2.7406	-0.0097
967	5e+12	NDD	2.6425	2.6329	-0.0096
1204	1e+13	NDD	2.6663	2.6649	-0.0014
1284	1e+13	NDD	2.6476	2.6317	-0.0159
1292	5e+12	NDD	2.7559	2.7411	-0.0148
1364	1e+13	NDD	2.7721	2.7748	0.0027
1383	5e+12	NDD	2.5438	2.5469	0.0031
1388	5e+12	NDD	2.5634	2.5732	0.0098
1427	1e+13	NDD	2.7523	2.7641	0.0118
1666	0	CORRELATION	2.6495	2.6488	-0.0007

Test Statistics (µA)

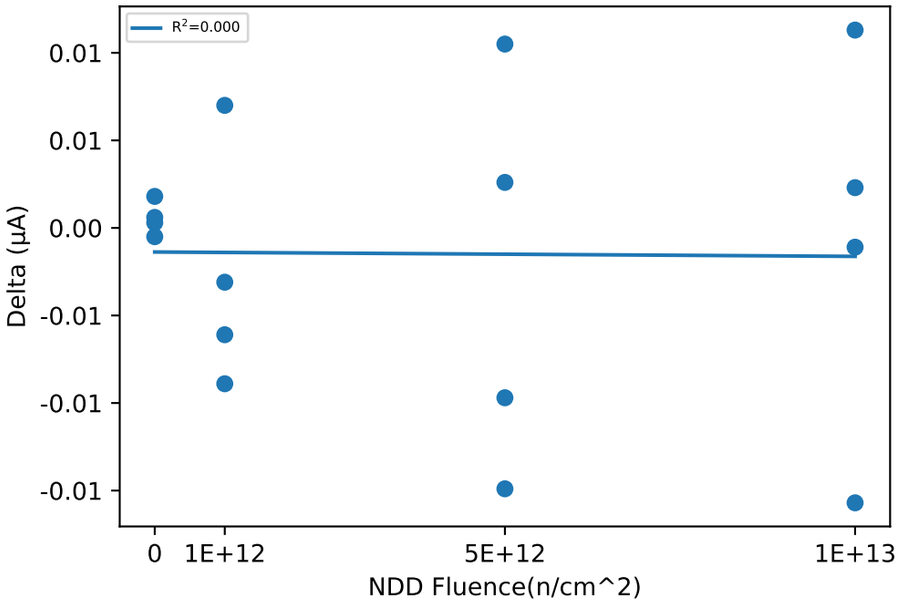
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6495	2.7529	2.8613	0.086562	2.6488	2.7531	2.863	0.087556	-0.0007	0.000225	0.0017	0.0010372
1e+12	2.6293	2.7036	2.7507	0.058606	2.6264	2.7005	2.7569	0.059949	-0.0097	-0.003075	0.0062	0.0067805
5e+12	2.5438	2.6264	2.7559	0.0963	2.5469	2.6235	2.7411	0.086247	-0.0148	-0.002875	0.0098	0.011311
1e+13	2.6476	2.7096	2.7721	0.061775	2.6317	2.7089	2.7748	0.071381	-0.0159	-0.0007	0.0118	0.011537

Device Test: 18.29 CURRENT|SS_0p3V/SS/14/14/0/1000/5/500kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

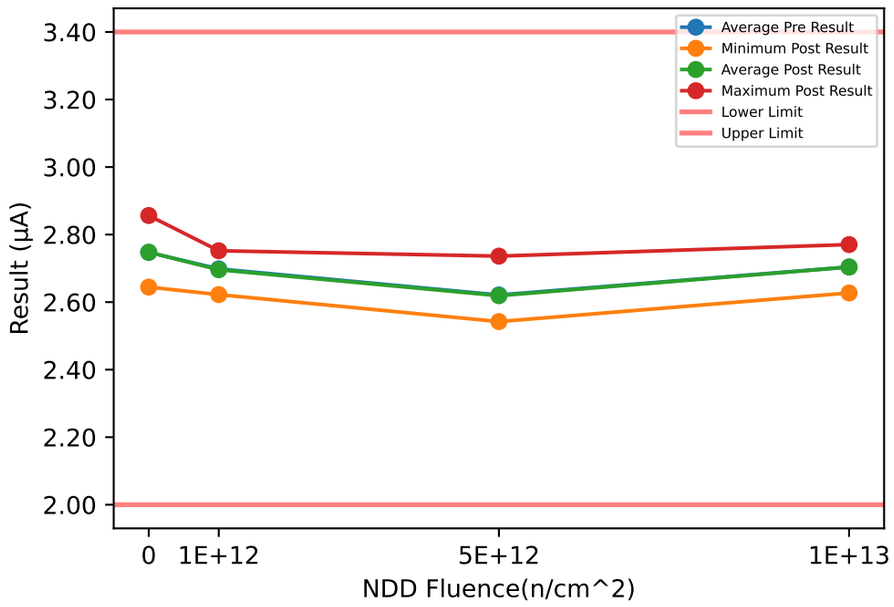
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7525	2.7528	0.0003
466	1e+12	NDD	2.7486	2.7556	0.007
762	0	CORRELATION	2.8593	2.8611	0.0018
769	1e+12	NDD	2.628	2.6249	-0.0031
887	1e+12	NDD	2.6833	2.6772	-0.0061
891	0	CORRELATION	2.7452	2.7458	0.0006
927	1e+12	NDD	2.7487	2.7398	-0.0089
967	5e+12	NDD	2.641	2.6313	-0.0097
1204	1e+13	NDD	2.6648	2.6637	-0.0011
1284	1e+13	NDD	2.6463	2.6306	-0.0157
1292	5e+12	NDD	2.7551	2.7402	-0.0149
1364	1e+13	NDD	2.771	2.7733	0.0023
1383	5e+12	NDD	2.5427	2.5453	0.0026
1388	5e+12	NDD	2.5617	2.5722	0.0105
1427	1e+13	NDD	2.751	2.7623	0.0113
1666	0	CORRELATION	2.6486	2.6481	-0.0005

Test Statistics (µA)

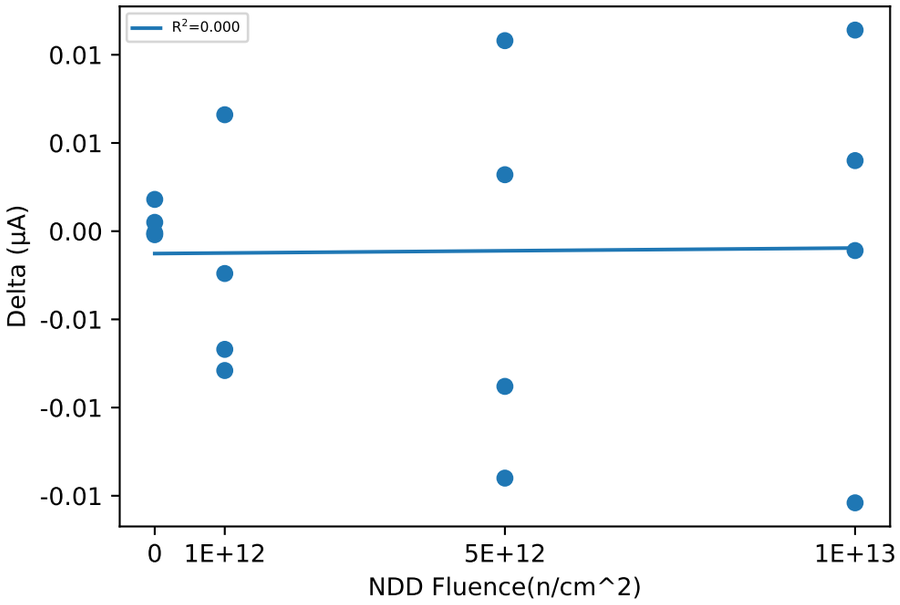
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6486	2.7514	2.8593	0.08612	2.6481	2.7519	2.8611	0.087058	-0.0005	0.00055	0.0018	0.00095394
1e+12	2.628	2.7022	2.7487	0.058247	2.6249	2.6994	2.7556	0.060094	-0.0089	-0.002775	0.007	0.0069337
5e+12	2.5427	2.6251	2.7551	0.096544	2.5453	2.6223	2.7402	0.086449	-0.0149	-0.002875	0.0105	0.011548
1e+13	2.6463	2.7083	2.771	0.061889	2.6306	2.7075	2.7733	0.071098	-0.0157	-0.0008	0.0113	0.011227

Device Test: 18.33 CURRENT|SS_0p3V/SS/4.5/4.5/0/1000/4.5/1MHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

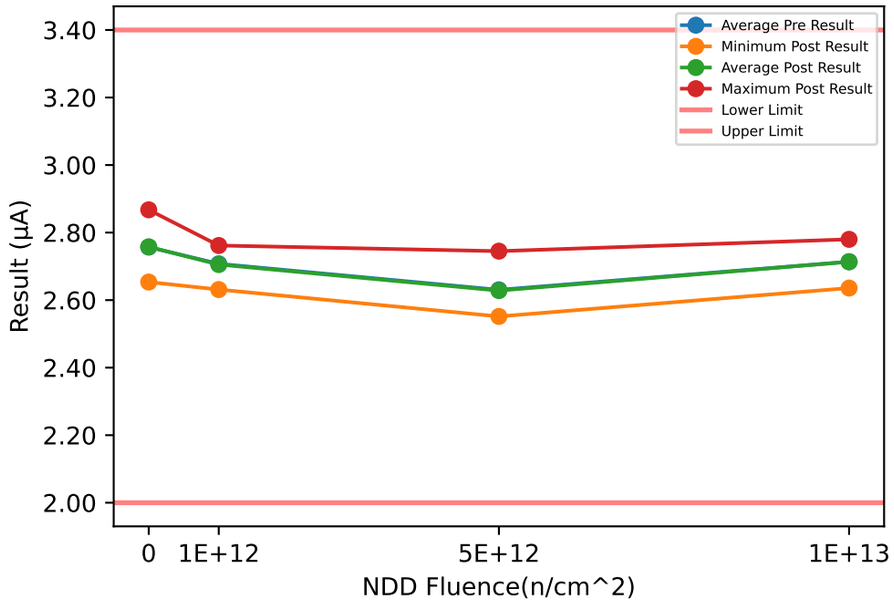
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.749	2.7488	-0.0002
466	1e+12	NDD	2.7455	2.7521	0.0066
762	0	CORRELATION	2.8547	2.8565	0.0018
769	1e+12	NDD	2.6246	2.6222	-0.0024
887	1e+12	NDD	2.6797	2.673	-0.0067
891	0	CORRELATION	2.7415	2.7414	-0.0001
927	1e+12	NDD	2.744	2.7361	-0.0079
967	5e+12	NDD	2.6369	2.6281	-0.0088
1204	1e+13	NDD	2.6601	2.659	-0.0011
1284	1e+13	NDD	2.6425	2.6271	-0.0154
1292	5e+12	NDD	2.7502	2.7362	-0.014
1364	1e+13	NDD	2.7664	2.7704	0.004
1383	5e+12	NDD	2.5391	2.5423	0.0032
1388	5e+12	NDD	2.5585	2.5693	0.0108
1427	1e+13	NDD	2.7473	2.7587	0.0114
1666	0	CORRELATION	2.6439	2.6444	0.0005

Test Statistics (µA)

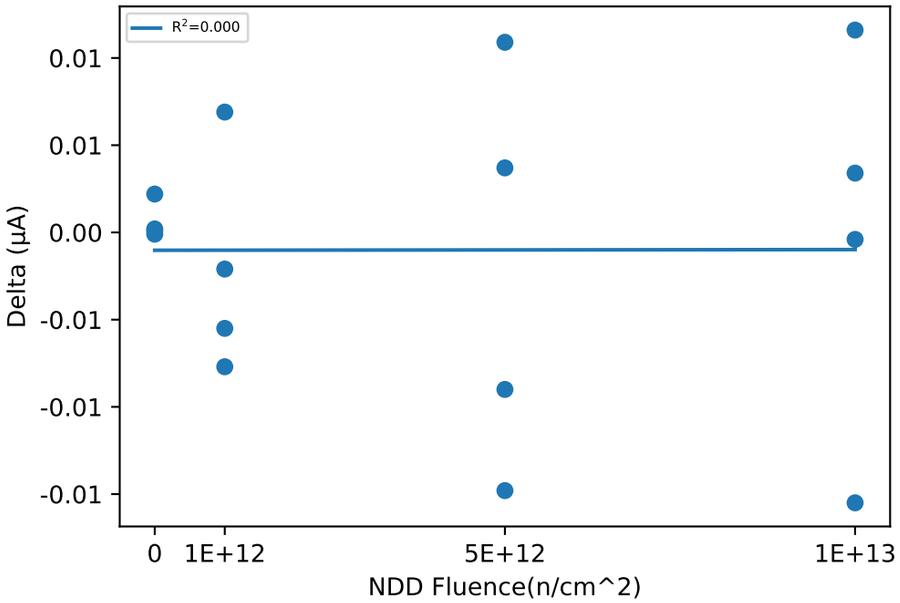
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6439	2.7473	2.8547	0.086145	2.6444	2.7478	2.8565	0.086697	-0.0002	0.0005	0.0018	0.00092014
1e+12	2.6246	2.6985	2.7455	0.058005	2.6222	2.6959	2.7521	0.059807	-0.0079	-0.0026	0.0066	0.0065722
5e+12	2.5391	2.6212	2.7502	0.095846	2.5423	2.619	2.7362	0.085968	-0.014	-0.0022	0.0108	0.011269
1e+13	2.6425	2.7041	2.7664	0.061855	2.6271	2.7038	2.7704	0.071506	-0.0154	-0.000275	0.0114	0.011314

Device Test: 18.37 CURRENT|SS_0p3V/SS/5/5/0/1000/5/1MHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

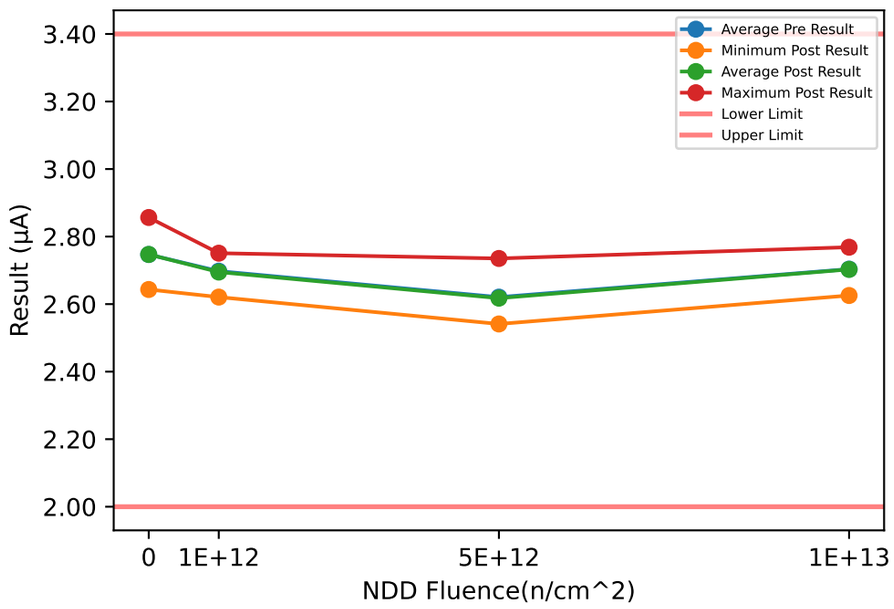
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.759	2.7589	-0.0001
466	1e+12	NDD	2.7548	2.7617	0.0069
762	0	CORRELATION	2.8652	2.8674	0.0022
769	1e+12	NDD	2.6334	2.6313	-0.0021
887	1e+12	NDD	2.688	2.6825	-0.0055
891	0	CORRELATION	2.7508	2.751	0.0002
927	1e+12	NDD	2.7535	2.7458	-0.0077
967	5e+12	NDD	2.6463	2.6373	-0.009
1204	1e+13	NDD	2.67	2.6696	-0.0004
1284	1e+13	NDD	2.6512	2.6357	-0.0155
1292	5e+12	NDD	2.7598	2.745	-0.0148
1364	1e+13	NDD	2.7766	2.78	0.0034
1383	5e+12	NDD	2.548	2.5517	0.0037
1388	5e+12	NDD	2.5676	2.5785	0.0109
1427	1e+13	NDD	2.7569	2.7685	0.0116
1666	0	CORRELATION	2.6534	2.6535	0.0001

Test Statistics (µA)

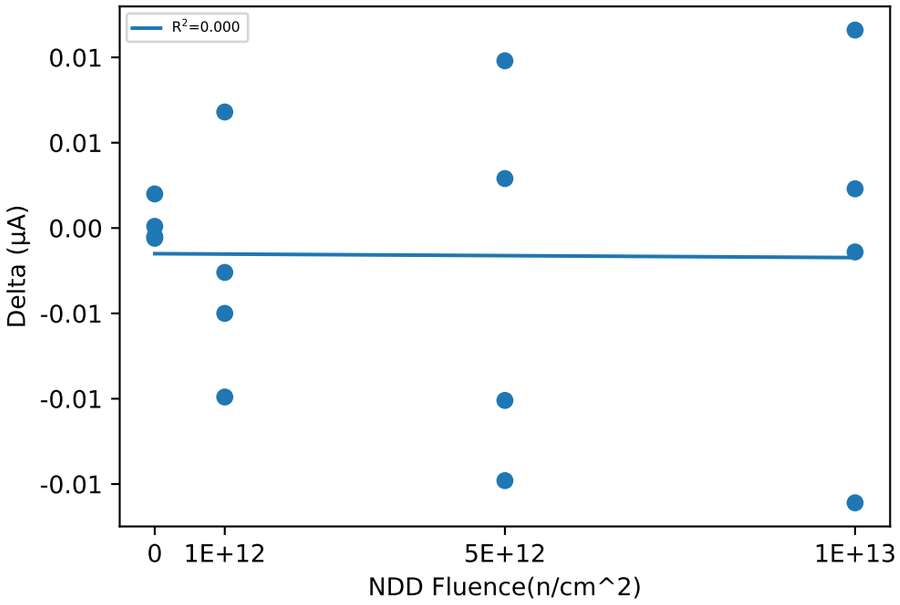
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6534	2.7571	2.8652	0.086569	2.6535	2.7577	2.8674	0.087442	-0.0001	0.0006	0.0022	0.0010739
1e+12	2.6334	2.7074	2.7548	0.058379	2.6313	2.7053	2.7617	0.060047	-0.0077	-0.0021	0.0069	0.006427
5e+12	2.548	2.6304	2.7598	0.096144	2.5517	2.6281	2.745	0.085727	-0.0148	-0.0023	0.0109	0.01171
1e+13	2.6512	2.7137	2.7766	0.062286	2.6357	2.7134	2.78	0.071711	-0.0155	-0.000225	0.0116	0.011348

Device Test: 18.41 CURRENT|SS_0p3V/SS/12/12/0/1000/5/1MHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

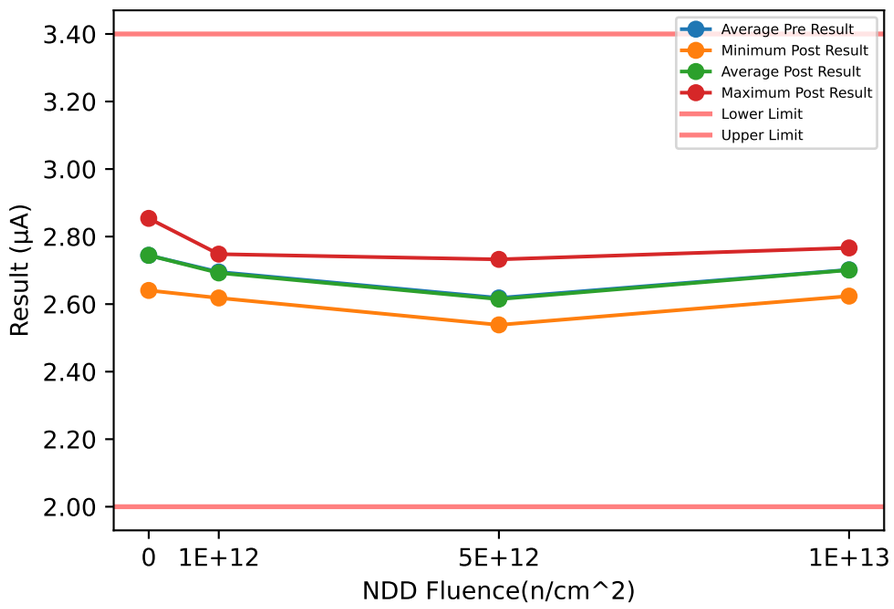
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7482	2.7476	-0.0006
466	1e+12	NDD	2.744	2.7508	0.0068
762	0	CORRELATION	2.8545	2.8565	0.002
769	1e+12	NDD	2.6234	2.6208	-0.0026
887	1e+12	NDD	2.6781	2.6731	-0.005
891	0	CORRELATION	2.741	2.7411	0.0001
927	1e+12	NDD	2.745	2.7351	-0.0099
967	5e+12	NDD	2.6369	2.6268	-0.0101
1204	1e+13	NDD	2.6607	2.6593	-0.0014
1284	1e+13	NDD	2.6416	2.6255	-0.0161
1292	5e+12	NDD	2.75	2.7352	-0.0148
1364	1e+13	NDD	2.7662	2.7685	0.0023
1383	5e+12	NDD	2.5383	2.5412	0.0029
1388	5e+12	NDD	2.5575	2.5673	0.0098
1427	1e+13	NDD	2.7462	2.7578	0.0116
1666	0	CORRELATION	2.6438	2.6433	-0.0005

Test Statistics (µA)

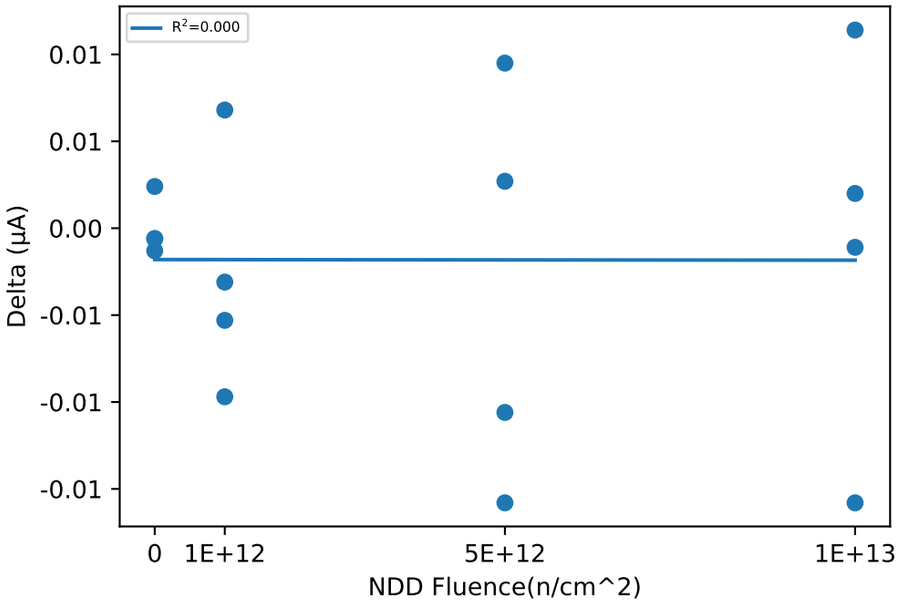
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6438	2.7469	2.8545	0.086108	2.6433	2.7471	2.8565	0.087138	-0.0006	0.00025	0.002	0.0012069
1e+12	2.6234	2.6976	2.745	0.058554	2.6208	2.6949	2.7508	0.059741	-0.0099	-0.002675	0.0068	0.0070092
5e+12	2.5383	2.6207	2.75	0.096203	2.5412	2.6176	2.7352	0.086181	-0.0148	-0.00305	0.0098	0.011377
1e+13	2.6416	2.7037	2.7662	0.061693	2.6255	2.7028	2.7685	0.071202	-0.0161	-0.0009	0.0116	0.011515

Device Test: 18.45 CURRENT|SS_0p3V/SS/14/14/0/1000/5/1MHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

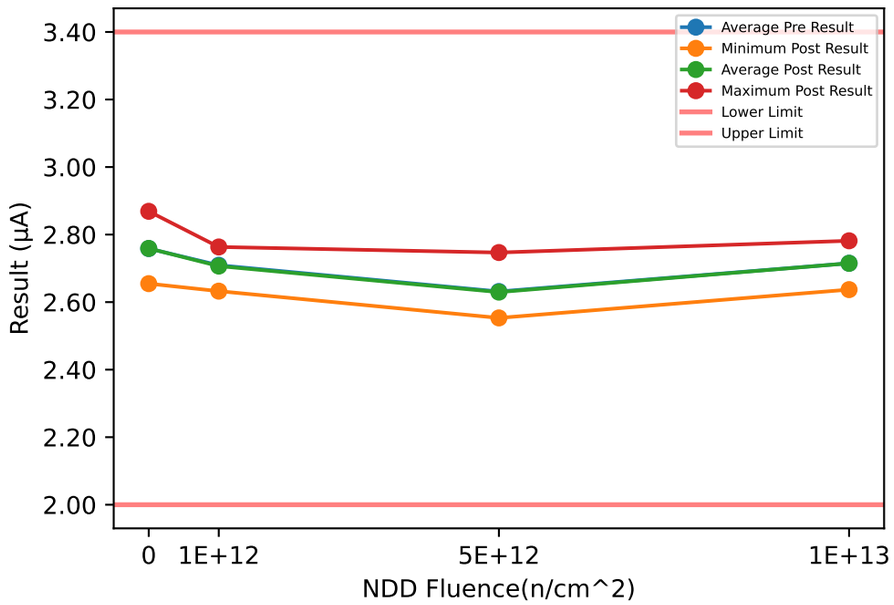
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7456	2.745	-0.0006
466	1e+12	NDD	2.7412	2.748	0.0068
762	0	CORRELATION	2.8515	2.8539	0.0024
769	1e+12	NDD	2.6213	2.6182	-0.0031
887	1e+12	NDD	2.676	2.6707	-0.0053
891	0	CORRELATION	2.7391	2.7385	-0.0006
927	1e+12	NDD	2.7423	2.7326	-0.0097
967	5e+12	NDD	2.6342	2.6236	-0.0106
1204	1e+13	NDD	2.6585	2.6574	-0.0011
1284	1e+13	NDD	2.6395	2.6237	-0.0158
1292	5e+12	NDD	2.7483	2.7325	-0.0158
1364	1e+13	NDD	2.7644	2.7664	0.002
1383	5e+12	NDD	2.5358	2.5385	0.0027
1388	5e+12	NDD	2.555	2.5645	0.0095
1427	1e+13	NDD	2.7443	2.7557	0.0114
1666	0	CORRELATION	2.6418	2.6405	-0.0013

Test Statistics (µA)

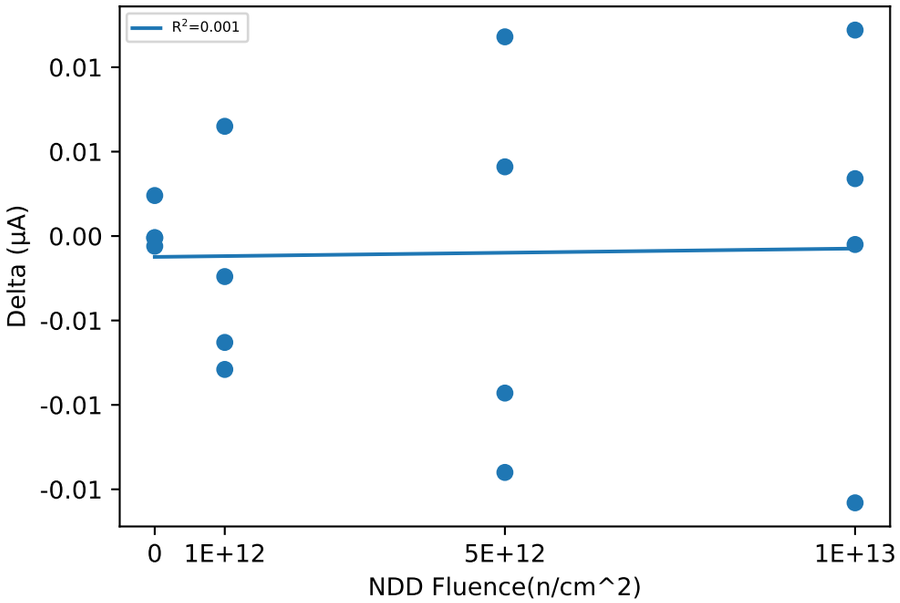
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6418	2.7445	2.8515	0.085687	2.6405	2.7445	2.8539	0.087217	-0.0013	-2.5e-05	0.0024	0.00165
1e+12	2.6213	2.6952	2.7423	0.058207	2.6182	2.6924	2.748	0.059677	-0.0097	-0.002825	0.0068	0.0069787
5e+12	2.5358	2.6183	2.7483	0.09655	2.5385	2.6148	2.7325	0.086183	-0.0158	-0.00355	0.0095	0.011678
1e+13	2.6395	2.7017	2.7644	0.061863	2.6237	2.7008	2.7664	0.071052	-0.0158	-0.000875	0.0114	0.01128

Device Test: 18.5 CURRENT|SS_0p3V/SS/5/5/0/1000/5/100kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

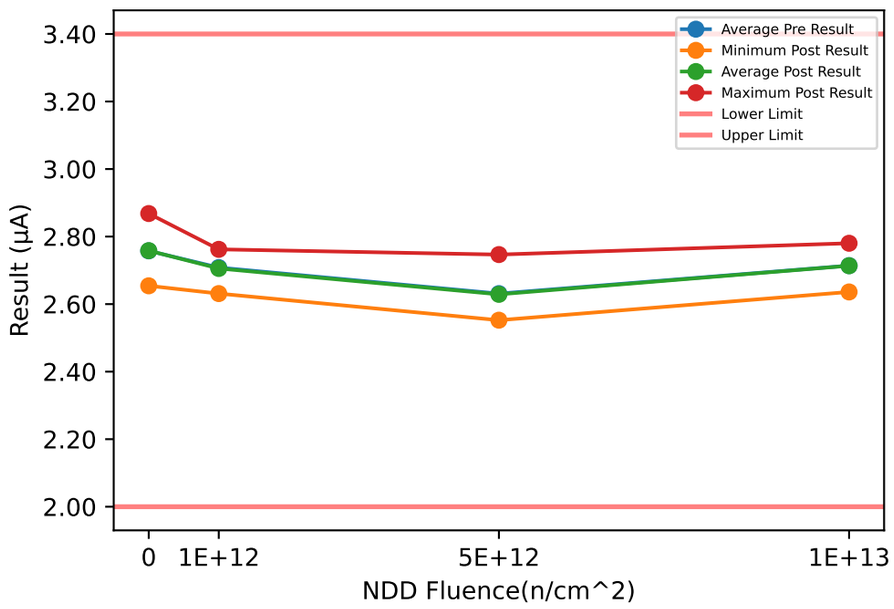
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7606	2.76	-0.0006
466	1e+12	NDD	2.7568	2.7633	0.0065
762	0	CORRELATION	2.8665	2.8689	0.0024
769	1e+12	NDD	2.6349	2.6325	-0.0024
887	1e+12	NDD	2.6898	2.6835	-0.0063
891	0	CORRELATION	2.7527	2.7526	-0.0001
927	1e+12	NDD	2.7553	2.7474	-0.0079
967	5e+12	NDD	2.6478	2.6385	-0.0093
1204	1e+13	NDD	2.6712	2.6707	-0.0005
1284	1e+13	NDD	2.6528	2.637	-0.0158
1292	5e+12	NDD	2.7608	2.7468	-0.014
1364	1e+13	NDD	2.7782	2.7816	0.0034
1383	5e+12	NDD	2.5491	2.5532	0.0041
1388	5e+12	NDD	2.5681	2.5799	0.0118
1427	1e+13	NDD	2.7581	2.7703	0.0122
1666	0	CORRELATION	2.6548	2.6547	-0.0001

Test Statistics (µA)

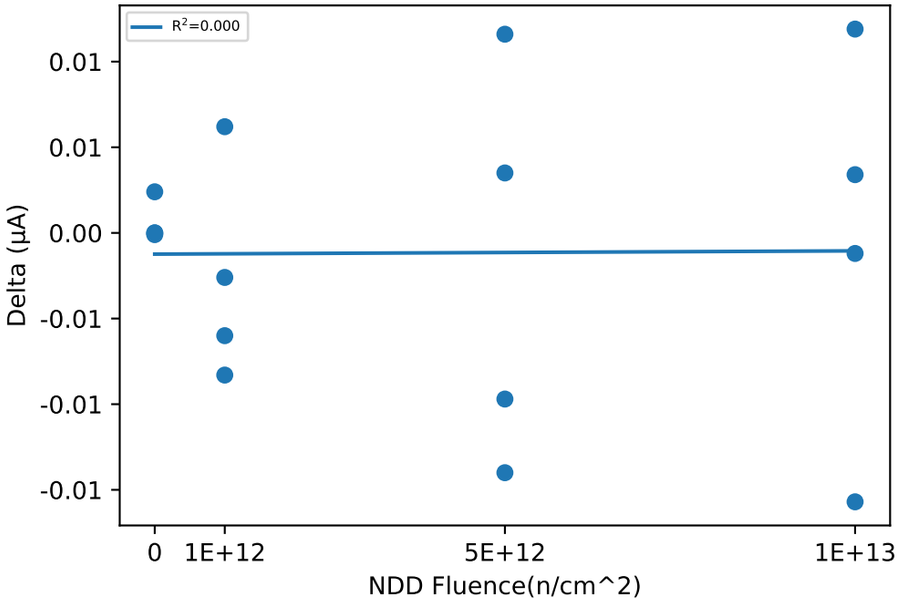
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6548	2.7586	2.8665	0.086517	2.6547	2.7591	2.8689	0.087557	-0.0006	0.0004	0.0024	0.001354
1e+12	2.6349	2.7092	2.7568	0.05856	2.6325	2.7067	2.7633	0.060288	-0.0079	-0.002525	0.0065	0.0064448
5e+12	2.5491	2.6315	2.7608	0.096252	2.5532	2.6296	2.7468	0.085872	-0.014	-0.00185	0.0118	0.0119
1e+13	2.6528	2.7151	2.7782	0.062287	2.637	2.7149	2.7816	0.071972	-0.0158	-0.000175	0.0122	0.011693

Device Test: 18.9 CURRENT|SS_0p3V/SS/12/12/0/1000/5/100kHz//@I_SS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 2.0, Upper Limit = 3.4 (µA))

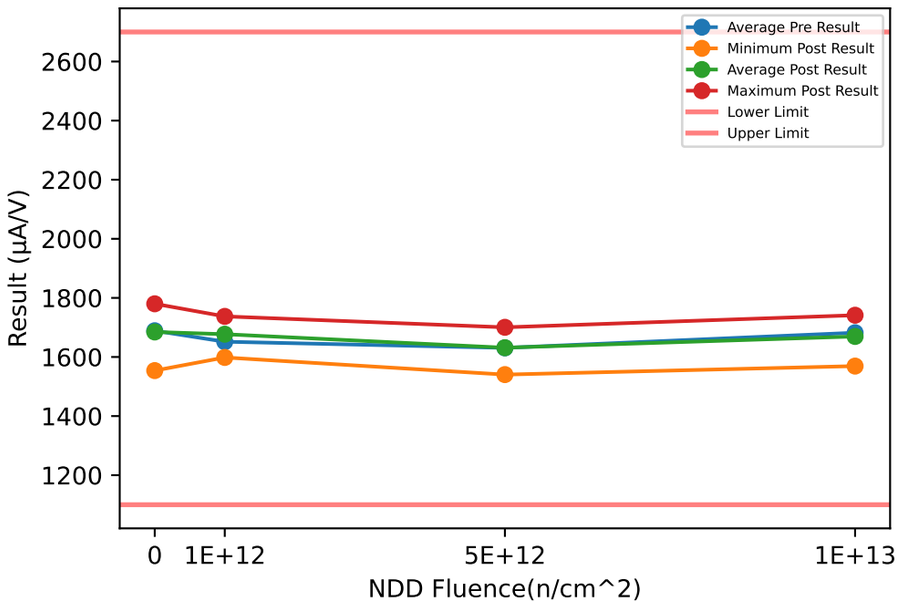
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.7591	2.759	-0.0001
466	1e+12	NDD	2.756	2.7622	0.0062
762	0	CORRELATION	2.8658	2.8682	0.0024
769	1e+12	NDD	2.6338	2.6312	-0.0026
887	1e+12	NDD	2.6887	2.6827	-0.006
891	0	CORRELATION	2.7518	2.7518	0
927	1e+12	NDD	2.7544	2.7461	-0.0083
967	5e+12	NDD	2.6474	2.6377	-0.0097
1204	1e+13	NDD	2.6705	2.6693	-0.0012
1284	1e+13	NDD	2.6517	2.636	-0.0157
1292	5e+12	NDD	2.7607	2.7467	-0.014
1364	1e+13	NDD	2.7768	2.7802	0.0034
1383	5e+12	NDD	2.5489	2.5524	0.0035
1388	5e+12	NDD	2.5673	2.5789	0.0116
1427	1e+13	NDD	2.757	2.7689	0.0119
1666	0	CORRELATION	2.6542	2.6542	0

Test Statistics (µA)

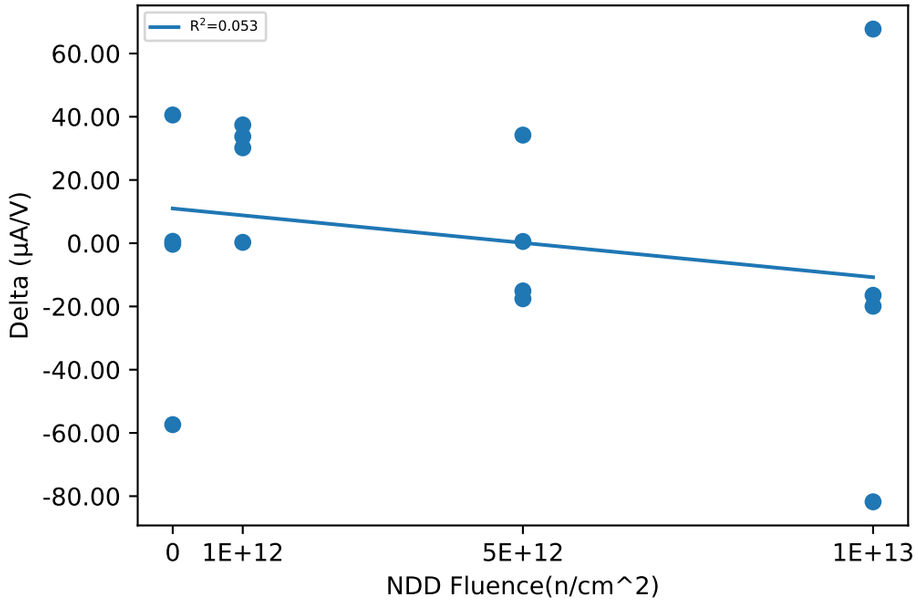
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.6542	2.7577	2.8658	0.086477	2.6542	2.7583	2.8682	0.087479	-0.0001	0.000575	0.0024	0.0012176
1e+12	2.6338	2.7082	2.756	0.058694	2.6312	2.7056	2.7622	0.060287	-0.0083	-0.002675	0.0062	0.0063631
5e+12	2.5489	2.6311	2.7607	0.096418	2.5524	2.6289	2.7467	0.086229	-0.014	-0.00215	0.0116	0.01181
1e+13	2.6517	2.714	2.7768	0.062092	2.636	2.7136	2.7802	0.071828	-0.0157	-0.0004	0.0119	0.011554

Device Test: 19.1 LEVEL|TRANSCONDUCTANCE//4.5/4.5/0/0/4.5/500kHz//@EA_GM

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



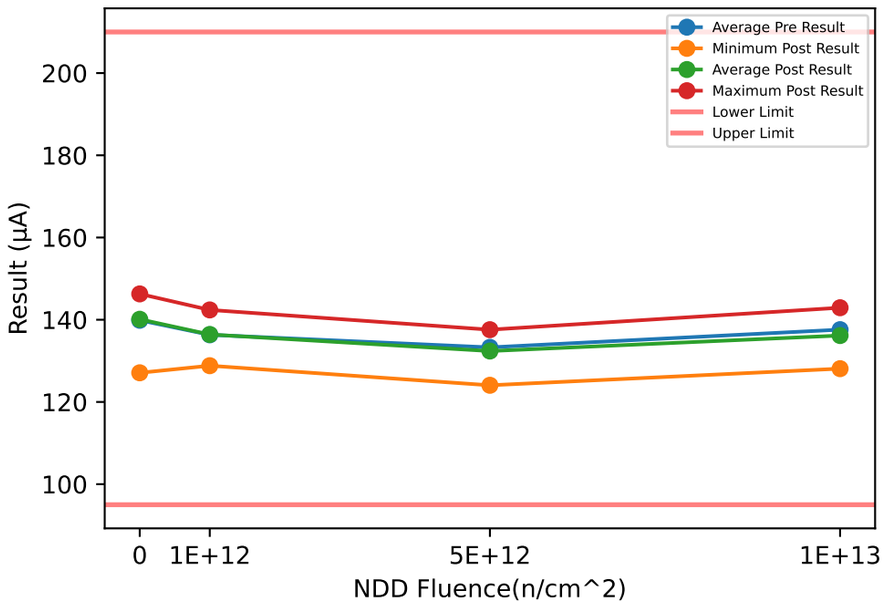
Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

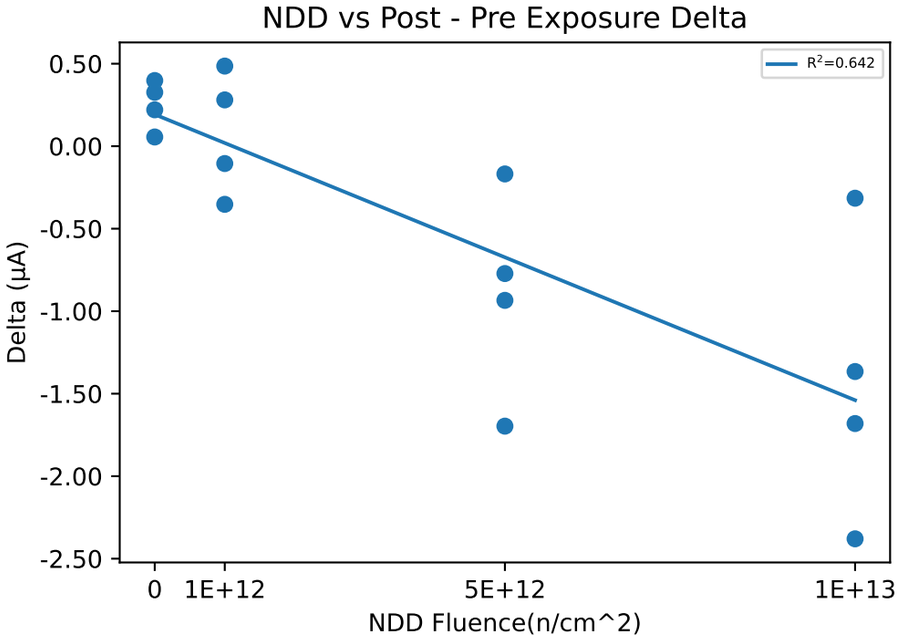
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1703.7	1704.3	0.597
466	1e+12	NDD	1703.7	1737.4	33.724
762	0	CORRELATION	1739.5	1780	40.556
769	1e+12	NDD	1568.2	1598.4	30.181
887	1e+12	NDD	1649.8	1650.1	0.2758
891	0	CORRELATION	1554.3	1554	-0.3383
927	1e+12	NDD	1685.2	1722.6	37.408
967	5e+12	NDD	1666.2	1700.4	34.19
1204	1e+13	NDD	1617.1	1684.8	67.726
1284	1e+13	NDD	1651	1569.2	-81.787
1292	5e+12	NDD	1667.6	1650.1	-17.566
1364	1e+13	NDD	1757.8	1741.3	-16.475
1383	5e+12	NDD	1649.8	1634.7	-15.095
1388	5e+12	NDD	1539.9	1540.4	0.5514
1427	1e+13	NDD	1702.5	1682.5	-19.925
1666	0	CORRELATION	1757.8	1700.4	-57.376

Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1554.3	1688.8	1757.8	92.45	1554	1684.7	1780	94.536	-57.376	-4.1403	40.556	40.285
1e+12	1568.2	1651.7	1703.7	59.981	1598.4	1677.1	1737.4	64.877	0.2758	25.397	37.408	17.006
5e+12	1539.9	1630.9	1667.6	61.227	1540.4	1631.4	1700.4	66.847	-17.566	0.5201	34.19	23.837
1e+13	1617.1	1682.1	1757.8	61.479	1569.2	1669.5	1741.3	72.171	-81.787	-12.615	67.726	61.395

Device Test: 19.10 CURRENT|EA_SOURCE//12/12/0/0/5/500kHz//@EA_I_SOURCE





Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

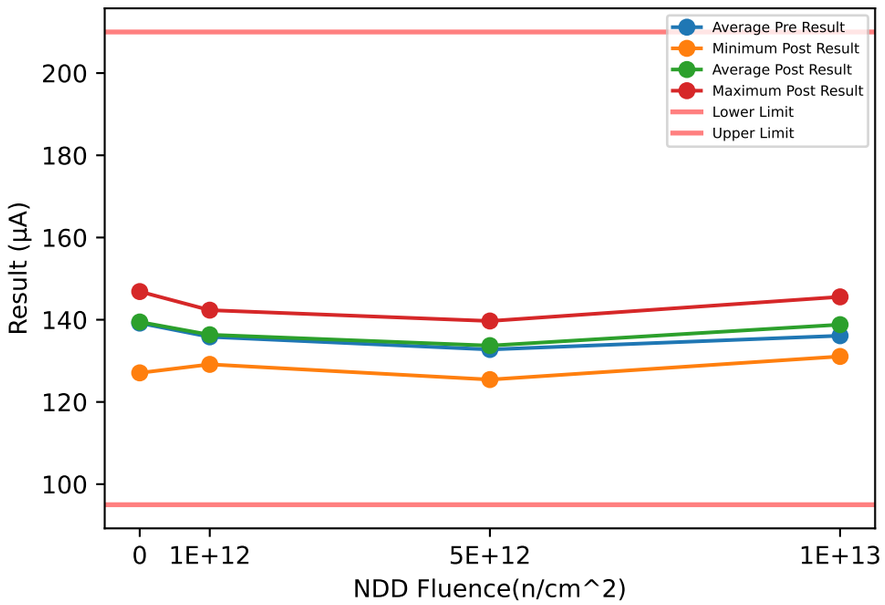
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	144.27	144.49	0.2206
466	1e+12	NDD	142.1	142.38	0.2806
762	0	CORRELATION	145.89	146.28	0.398
769	1e+12	NDD	128.33	128.82	0.4856
887	1e+12	NDD	136.18	135.83	-0.3524
891	0	CORRELATION	127.04	127.09	0.0558
927	1e+12	NDD	138.72	138.61	-0.1051
967	5e+12	NDD	138.35	137.58	-0.7719
1204	1e+13	NDD	135.01	134.7	-0.3153
1284	1e+13	NDD	130.48	128.1	-2.3797
1292	5e+12	NDD	136.71	135.01	-1.6968
1364	1e+13	NDD	144.6	142.92	-1.681
1383	5e+12	NDD	133.82	132.89	-0.9344
1388	5e+12	NDD	124.22	124.06	-0.1682
1427	1e+13	NDD	140.26	138.9	-1.3657
1666	0	CORRELATION	142.28	142.6	0.3266

Test Statistics (µA)

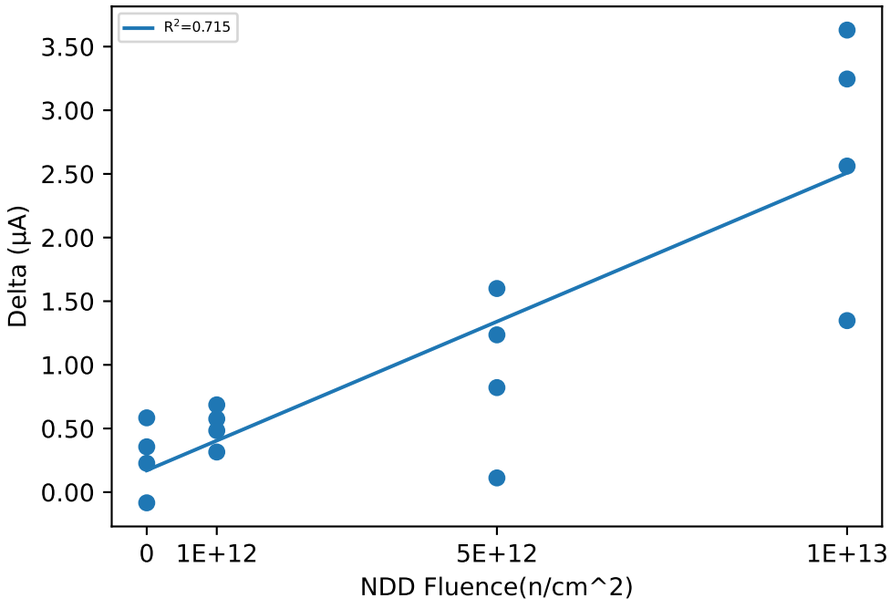
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127.04	139.87	145.89	8.6805	127.09	140.12	146.28	8.8128	0.0558	0.25025	0.398	0.14872
1e+12	128.33	136.33	142.1	5.8596	128.82	136.41	142.38	5.7302	-0.3524	0.077175	0.4856	0.37681
5e+12	124.22	133.28	138.35	6.3183	124.06	132.38	137.58	5.8736	-1.6968	-0.89282	-0.1682	0.62923
1e+13	130.48	137.59	144.6	6.1518	128.1	136.15	142.92	6.3334	-2.3797	-1.4354	-0.3153	0.85858

Device Test: 19.11 CURRENT|EA_SINK//12/12/0/0/5/500kHz//@EA_I_SINK

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



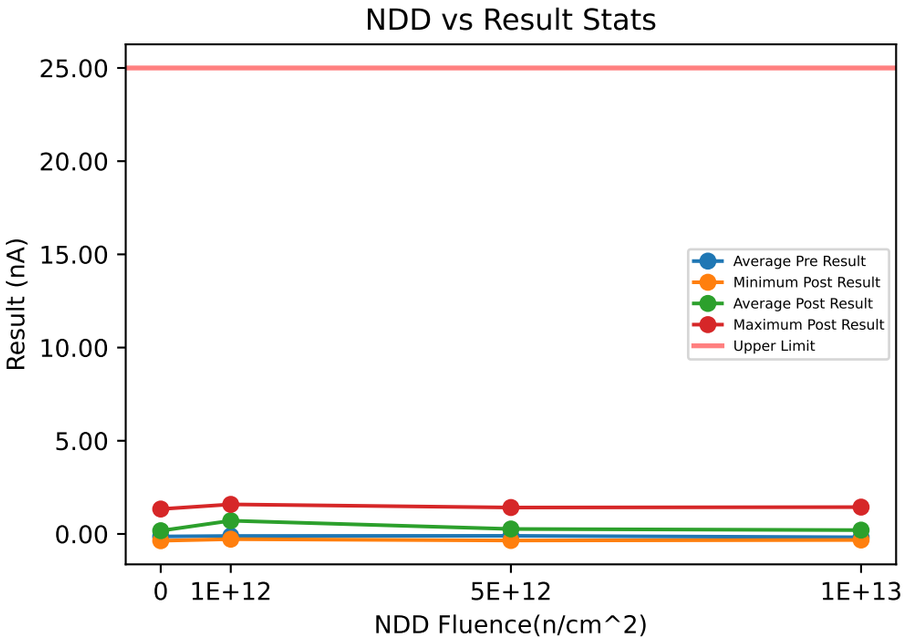
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

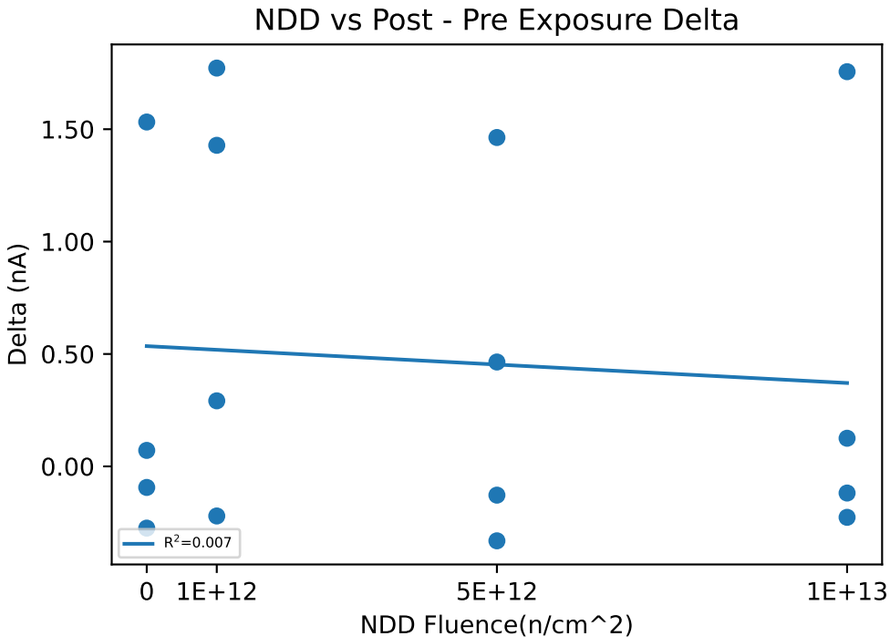
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	142.29	142.51	0.2267
466	1e+12	NDD	141.75	142.33	0.5756
762	0	CORRELATION	146.27	146.85	0.5838
769	1e+12	NDD	128.66	129.14	0.4835
887	1e+12	NDD	134.74	135.06	0.3153
891	0	CORRELATION	127.16	127.08	-0.0838
927	1e+12	NDD	138.18	138.87	0.6858
967	5e+12	NDD	138.46	139.69	1.2357
1204	1e+13	NDD	134.38	138.01	3.6298
1284	1e+13	NDD	129.72	131.07	1.3475
1292	5e+12	NDD	136.55	136.66	0.1118
1364	1e+13	NDD	142.32	145.56	3.2455
1383	5e+12	NDD	132.2	133.02	0.8213
1388	5e+12	NDD	123.84	125.44	1.5996
1427	1e+13	NDD	138.01	140.57	2.5616
1666	0	CORRELATION	141	141.36	0.3562

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127.16	139.18	146.27	8.3209	127.08	139.45	146.85	8.5819	-0.0838	0.27072	0.5838	0.27866
1e+12	128.66	135.83	141.75	5.5752	129.14	136.35	142.33	5.6489	0.3153	0.51505	0.6858	0.15676
5e+12	123.84	132.76	138.46	6.4965	125.44	133.7	139.69	6.1454	0.1118	0.9421	1.5996	0.63836
1e+13	129.72	136.11	142.32	5.3534	131.07	138.8	145.56	6.0362	1.3475	2.6961	3.6298	1.0017

Device Test: 19.12 CURRENT|EA//12/12/0/0/5/500kHz//@EA_IB





Test Results (Upper Limit = 25.0 (nA))

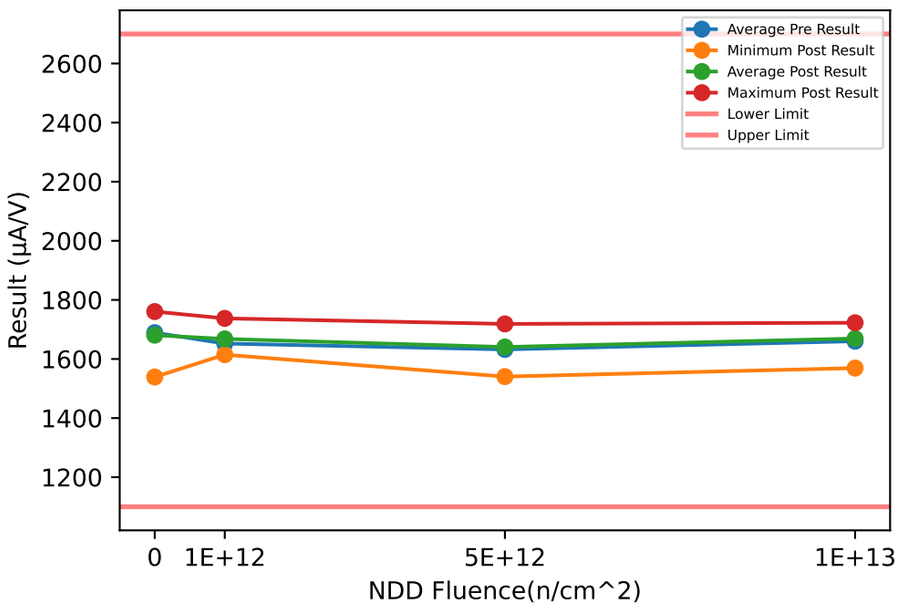
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.0882	-0.3629	-0.2747
466	1e+12	NDD	-0.1038	1.3246	1.4284
762	0	CORRELATION	-0.0786	-0.0075	0.0711
769	1e+12	NDD	-0.1855	1.5865	1.772
887	1e+12	NDD	-0.0598	-0.2805	-0.2207
891	0	CORRELATION	-0.1775	-0.2712	-0.0937
927	1e+12	NDD	-0.0808	0.2108	0.2916
967	5e+12	NDD	-0.0449	1.4182	1.4631
1204	1e+13	NDD	-0.1026	-0.2212	-0.1186
1284	1e+13	NDD	-0.0976	-0.3243	-0.2267
1292	5e+12	NDD	-0.1713	-0.2993	-0.128
1364	1e+13	NDD	-0.1949	-0.0698	0.1251
1383	5e+12	NDD	-0.0192	-0.3504	-0.3312
1388	5e+12	NDD	-0.1662	0.2981	0.4643
1427	1e+13	NDD	-0.3159	1.44	1.7559
1666	0	CORRELATION	-0.1949	1.3371	1.532

Test Statistics (nA)

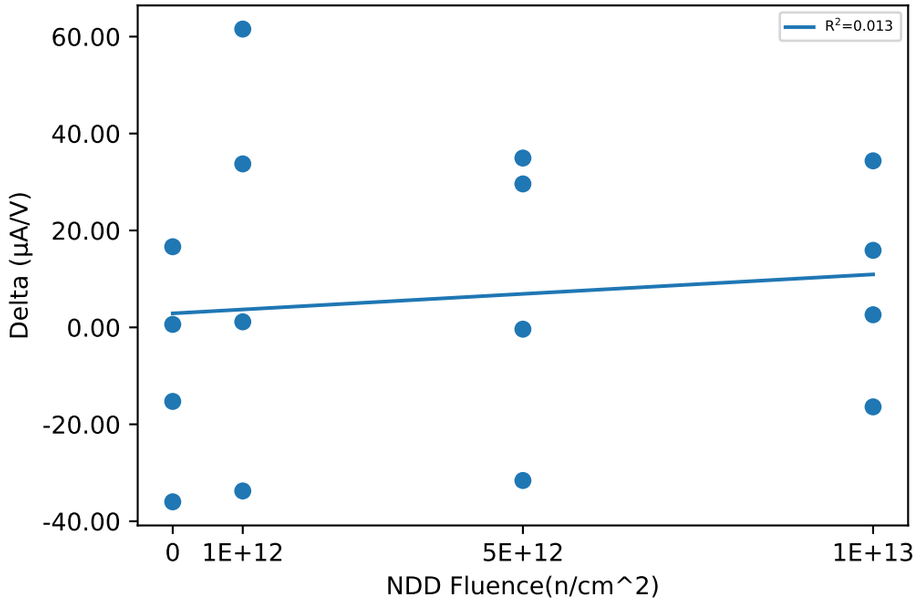
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1949	-0.1348	-0.0786	0.059904	-0.3629	0.17388	1.3371	0.78998	-0.2747	0.30868	1.532	0.82769
1e+12	-0.1855	-0.10748	-0.0598	0.055033	-0.2805	0.71035	1.5865	0.89	-0.2207	0.81783	1.772	0.93785
5e+12	-0.1713	-0.1004	-0.0192	0.079645	-0.3504	0.26665	1.4182	0.82221	-0.3312	0.36705	1.4631	0.80486
1e+13	-0.3159	-0.17775	-0.0976	0.10239	-0.3243	0.20617	1.44	0.82916	-0.2267	0.38393	1.7559	0.92641

Device Test: 19.13 LEVEL|TRANSCONDUCTANCE//14/14/0/0/5/500kHz//@EA_GM

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

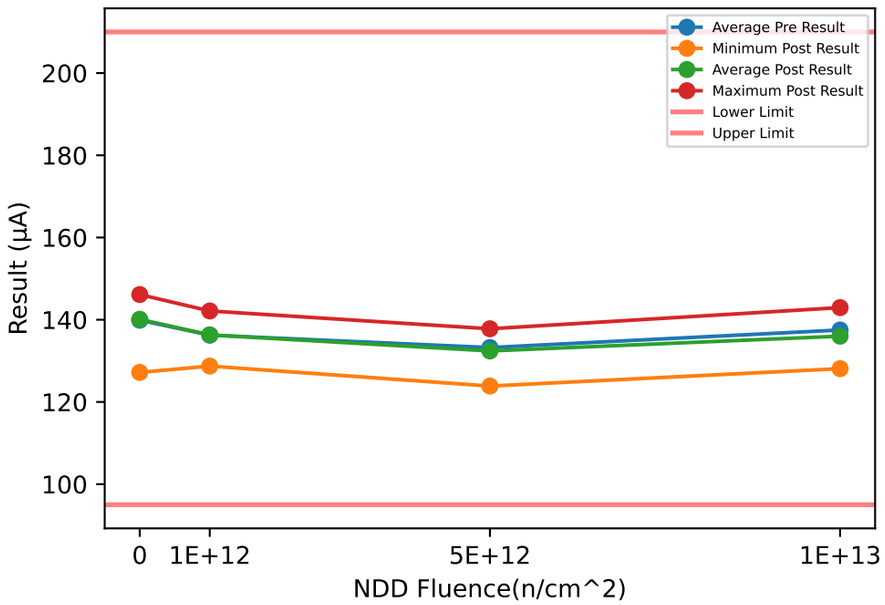
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1759.8	1760.5	0.6186
466	1e+12	NDD	1703.7	1737.4	33.733
762	0	CORRELATION	1758.6	1722.6	-35.995
769	1e+12	NDD	1553	1614.6	61.553
887	1e+12	NDD	1667	1633.2	-33.754
891	0	CORRELATION	1554.3	1539	-15.277
927	1e+12	NDD	1685.2	1686.3	1.1433
967	5e+12	NDD	1683.8	1718.7	34.938
1204	1e+13	NDD	1650.4	1684.8	34.367
1284	1e+13	NDD	1585.6	1569.2	-16.402
1292	5e+12	NDD	1685.2	1684.8	-0.3723
1364	1e+13	NDD	1720	1722.6	2.6048
1383	5e+12	NDD	1649.8	1618.2	-31.595
1388	5e+12	NDD	1510.8	1540.4	29.602
1427	1e+13	NDD	1684.5	1700.4	15.895
1666	0	CORRELATION	1683.8	1700.4	16.639

Test Statistics (µA/V)

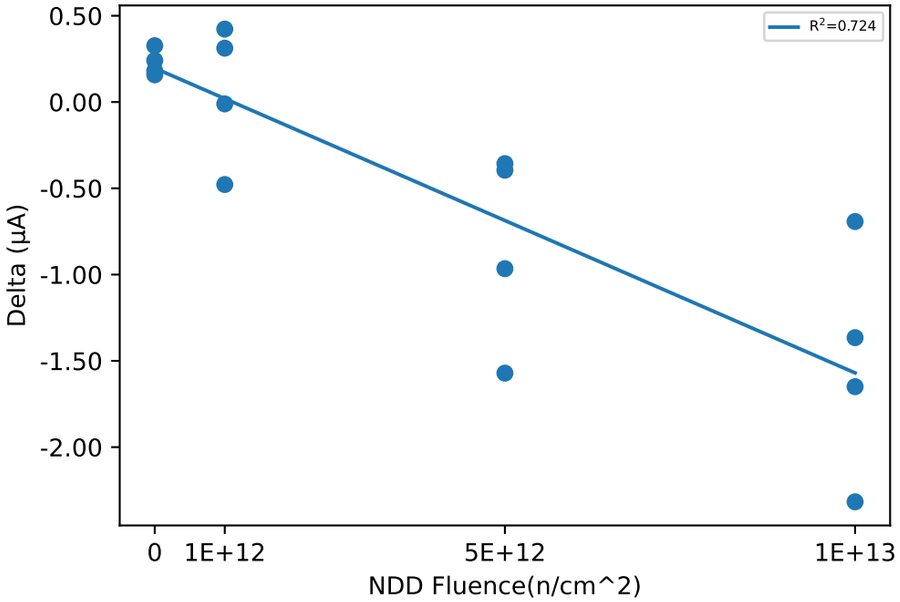
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1554.3	1689.1	1759.8	96.664	1539	1680.6	1760.5	97.601	-35.995	-8.5037	16.639	22.487
1e+12	1553	1652.2	1703.7	67.812	1614.6	1667.9	1737.4	55.427	-33.754	15.669	61.553	41.171
5e+12	1510.8	1632.4	1685.2	82.696	1540.4	1640.5	1718.7	78.738	-31.595	8.1433	34.938	30.714
1e+13	1585.6	1660.1	1720	57.238	1569.2	1669.3	1722.6	68.49	-16.402	9.1162	34.367	21.425

Device Test: 19.14 CURRENT|EA_SOURCE//14/14/0/0/5/500kHz//@EA_I_SOURCE

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



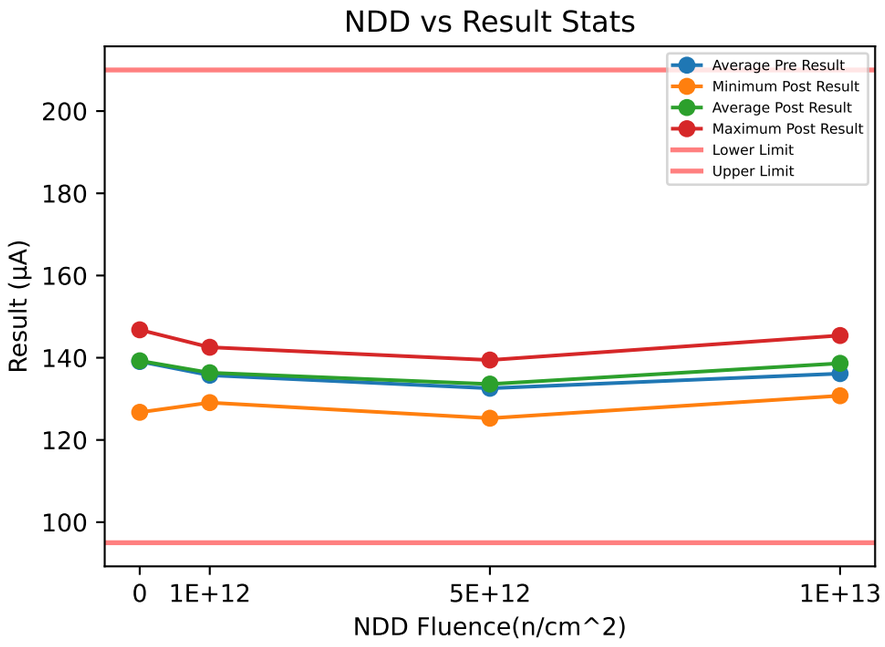
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

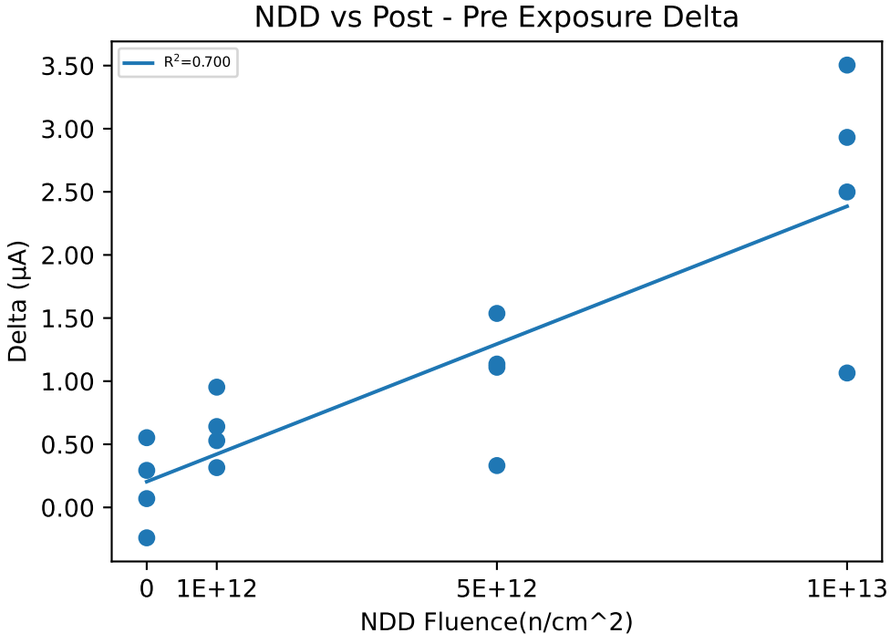
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	144.15	144.3	0.1577
466	1e+12	NDD	141.82	142.13	0.3121
762	0	CORRELATION	145.89	146.13	0.2408
769	1e+12	NDD	128.3	128.72	0.4228
887	1e+12	NDD	136.24	135.77	-0.4781
891	0	CORRELATION	127	127.19	0.1814
927	1e+12	NDD	138.65	138.64	-0.0108
967	5e+12	NDD	138.19	137.8	-0.3951
1204	1e+13	NDD	134.86	134.16	-0.6926
1284	1e+13	NDD	130.41	128.1	-2.3169
1292	5e+12	NDD	136.61	135.04	-1.5711
1364	1e+13	NDD	144.6	142.95	-1.6496
1383	5e+12	NDD	133.89	132.92	-0.9657
1388	5e+12	NDD	124.22	123.87	-0.3569
1427	1e+13	NDD	140.14	138.77	-1.3656
1666	0	CORRELATION	142.5	142.82	0.3266

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127	139.88	145.89	8.6963	127.19	140.11	146.13	8.7209	0.1577	0.22662	0.3266	0.075259
1e+12	128.3	136.25	141.82	5.7732	128.72	136.32	142.13	5.6917	-0.4781	0.0615	0.4228	0.40404
5e+12	124.22	133.23	138.19	6.2616	123.87	132.41	137.8	6.0334	-1.5711	-0.8222	-0.3569	0.57165
1e+13	130.41	137.5	144.6	6.1801	128.1	136	142.95	6.3726	-2.3169	-1.5062	-0.6926	0.67318

Device Test: 19.15 CURRENT|EA_SINK//14/14/0/0/5/500kHz//@EA_I_SINK





Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

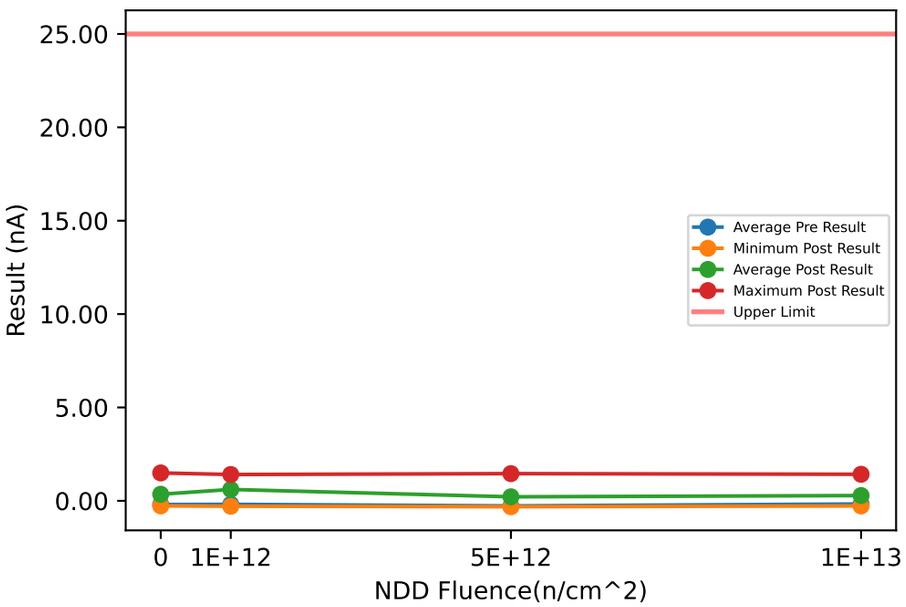
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	142.16	142.23	0.0695
466	1e+12	NDD	141.6	142.55	0.9525
762	0	CORRELATION	146.24	146.79	0.5523
769	1e+12	NDD	128.44	129.08	0.6405
887	1e+12	NDD	134.62	134.93	0.3152
891	0	CORRELATION	126.97	126.73	-0.241
927	1e+12	NDD	138.31	138.84	0.5289
967	5e+12	NDD	138.33	139.44	1.1102
1204	1e+13	NDD	134.35	137.85	3.5041
1284	1e+13	NDD	129.69	130.75	1.0648
1292	5e+12	NDD	136.11	136.44	0.3314
1364	1e+13	NDD	142.47	145.41	2.9313
1383	5e+12	NDD	132.07	133.21	1.1355
1388	5e+12	NDD	123.75	125.29	1.5366
1427	1e+13	NDD	138.04	140.54	2.4988
1666	0	CORRELATION	140.97	141.26	0.2933

Test Statistics (µA)

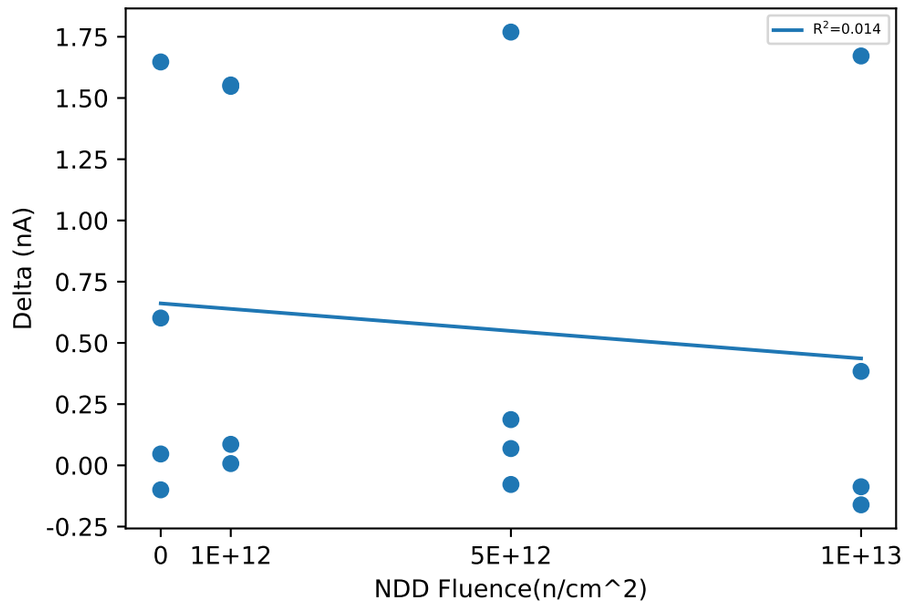
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.97	139.08	146.24	8.3849	126.73	139.25	146.79	8.6897	-0.241	0.16852	0.5523	0.33683
1e+12	128.44	135.74	141.6	5.6414	129.08	136.35	142.55	5.7591	0.3152	0.60928	0.9525	0.26566
5e+12	123.75	132.56	138.33	6.4227	125.29	133.59	139.44	6.0952	0.3314	1.0284	1.5366	0.50406
1e+13	129.69	136.14	142.47	5.4339	130.75	138.64	145.41	6.1162	1.0648	2.4998	3.5041	1.0415

Device Test: 19.16 CURRENT|EA//14/14/0/0/5/500kHz//@EA_IB

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 25.0 (nA))

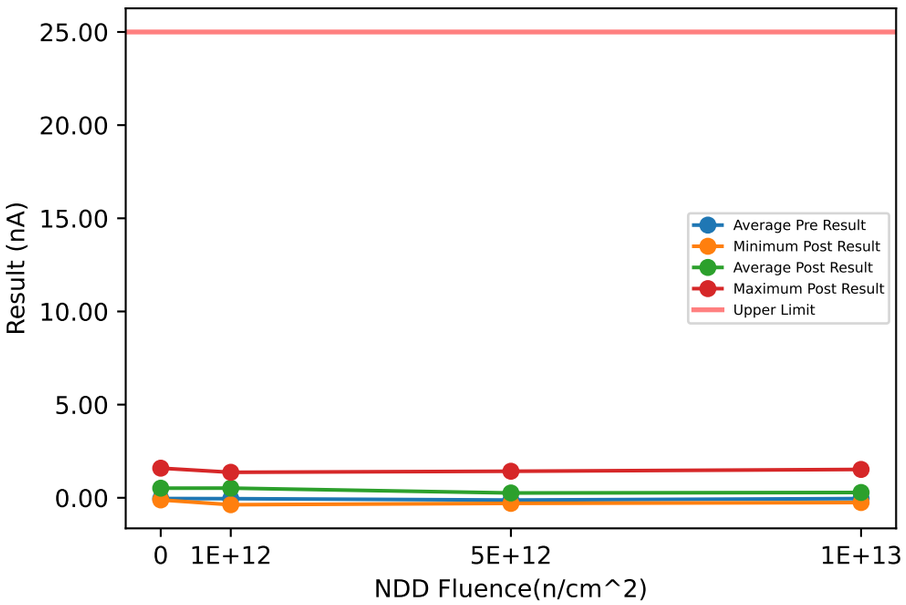
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.1101	-0.0636	0.0465
466	1e+12	NDD	-0.1444	1.4088	1.5532
762	0	CORRELATION	-0.3534	0.2482	0.6016
769	1e+12	NDD	-0.1761	1.3714	1.5475
887	1e+12	NDD	-0.2972	-0.2899	0.0073
891	0	CORRELATION	-0.1713	-0.2712	-0.0999
927	1e+12	NDD	-0.1401	-0.0542	0.0859
967	5e+12	NDD	-0.3136	1.4556	1.7692
1204	1e+13	NDD	-0.1557	-0.2431	-0.0874
1284	1e+13	NDD	-0.1132	-0.2743	-0.1611
1292	5e+12	NDD	-0.2025	-0.2805	-0.078
1364	1e+13	NDD	-0.1605	0.2233	0.3838
1383	5e+12	NDD	-0.3847	-0.3161	0.0686
1388	5e+12	NDD	-0.1881	-0.0012	0.1869
1427	1e+13	NDD	-0.2503	1.4213	1.6716
1666	0	CORRELATION	-0.1542	1.493	1.6472

Test Statistics (nA)

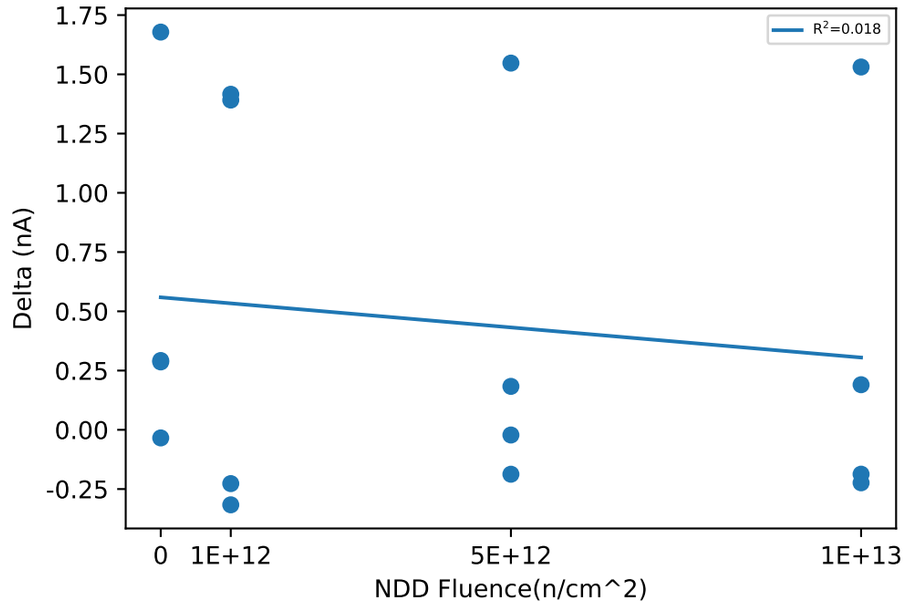
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3534	-0.19725	-0.1101	0.10725	-0.2712	0.3516	1.493	0.79031	-0.0999	0.54885	1.6472	0.79213
1e+12	-0.2972	-0.18945	-0.1401	0.073605	-0.2899	0.60903	1.4088	0.90715	0.0073	0.79848	1.5532	0.86879
5e+12	-0.3847	-0.27222	-0.1881	0.093632	-0.3161	0.21445	1.4556	0.83933	-0.078	0.48668	1.7692	0.86185
1e+13	-0.2503	-0.16992	-0.1132	0.057646	-0.2743	0.2818	1.4213	0.79302	-0.1611	0.45172	1.6716	0.84832

Device Test: 19.17 CURRENT|EA//4.5/4.5/0/0/4.5/100kHz//@EA_IB

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



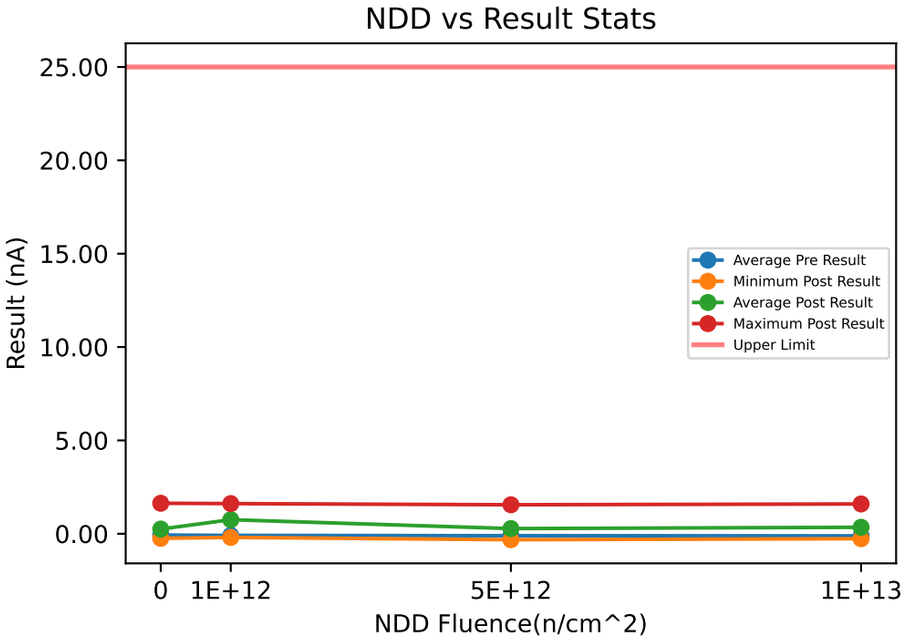
Test Results (Upper Limit = 25.0 (nA))

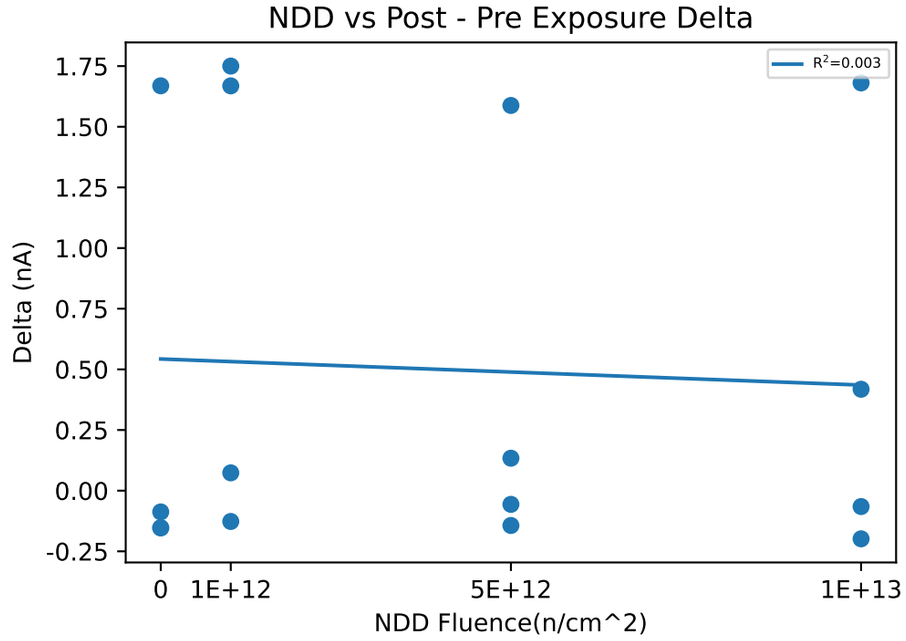
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.004	0.2825	0.2865
466	1e+12	NDD	-0.0476	1.3683	1.4159
762	0	CORRELATION	0.012	0.3044	0.2924
769	1e+12	NDD	-0.0761	1.3153	1.3914
887	1e+12	NDD	-0.0098	-0.2368	-0.227
891	0	CORRELATION	-0.0808	-0.115	-0.0342
927	1e+12	NDD	-0.0558	-0.3723	-0.3165
967	5e+12	NDD	-0.123	1.4244	1.5474
1204	1e+13	NDD	-0.034	-0.2212	-0.1872
1284	1e+13	NDD	-0.032	-0.2556	-0.2236
1292	5e+12	NDD	-0.1775	-0.1994	-0.0219
1364	1e+13	NDD	-0.098	0.0923	0.1903
1383	5e+12	NDD	-0.0754	0.1079	0.1833
1388	5e+12	NDD	-0.1132	-0.3006	-0.1874
1427	1e+13	NDD	-0.0098	1.5211	1.5309
1666	0	CORRELATION	-0.0886	1.5897	1.6783

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0886	-0.04035	0.012	0.051724	-0.115	0.5154	1.5897	0.74168	-0.0342	0.55575	1.6783	0.76376
1e+12	-0.0761	-0.047325	-0.0098	0.027737	-0.3723	0.51863	1.3683	0.95237	-0.3165	0.56595	1.4159	0.96803
5e+12	-0.1775	-0.12227	-0.0754	0.04215	-0.3006	0.25808	1.4244	0.79672	-0.1874	0.38035	1.5474	0.79267
1e+13	-0.098	-0.04345	-0.0098	0.037984	-0.2556	0.28415	1.5211	0.83936	-0.2236	0.3276	1.5309	0.82374

Device Test: 19.18 CURRENT|EA//4.5/4.5/0/0/4.5/1MHz//@EA_IB





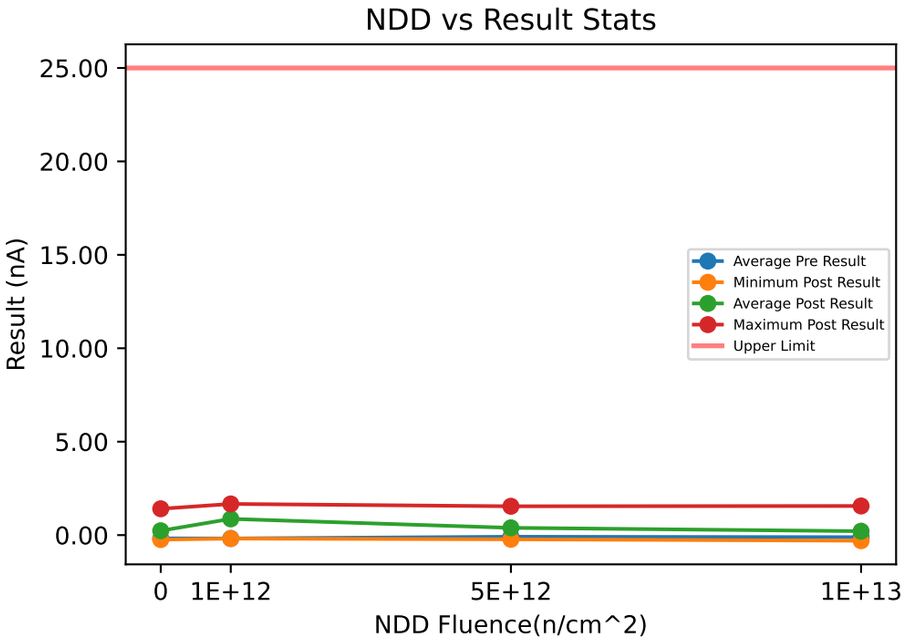
Test Results (Upper Limit = 25.0 (nA))

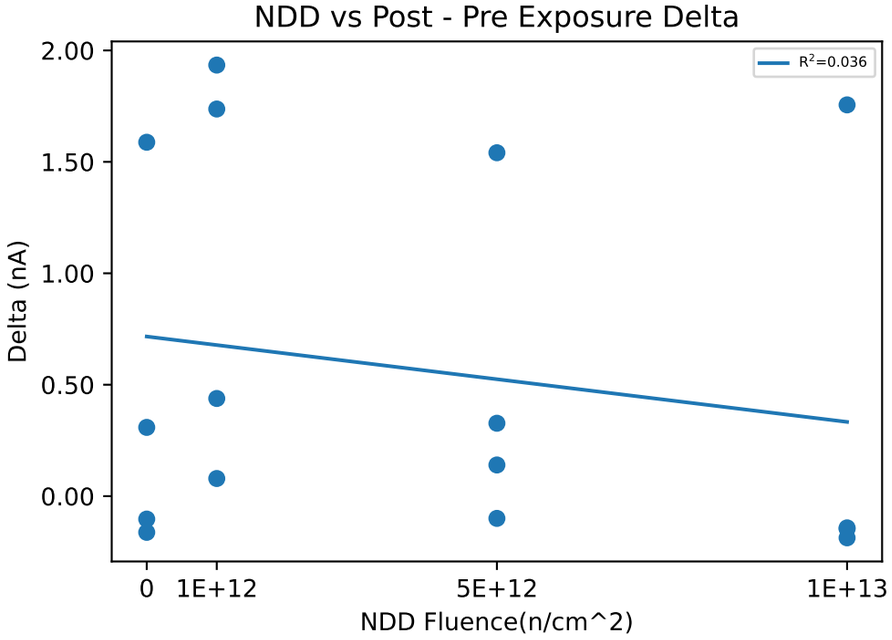
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.0851	-0.1727	-0.0876
466	1e+12	NDD	-0.0726	1.5959	1.6685
762	0	CORRELATION	-0.091	-0.2444	-0.1534
769	1e+12	NDD	-0.1355	1.6146	1.7501
887	1e+12	NDD	-0.0692	-0.1962	-0.127
891	0	CORRELATION	-0.0589	-0.2118	-0.1529
927	1e+12	NDD	-0.0777	-0.0043	0.0734
967	5e+12	NDD	-0.0355	1.5523	1.5878
1204	1e+13	NDD	-0.1744	-0.2399	-0.0655
1284	1e+13	NDD	-0.0664	-0.2649	-0.1985
1292	5e+12	NDD	-0.0964	-0.2399	-0.1435
1364	1e+13	NDD	-0.1261	0.2919	0.418
1383	5e+12	NDD	-0.2628	-0.3193	-0.0565
1388	5e+12	NDD	-0.0196	0.1142	0.1338
1427	1e+13	NDD	-0.0848	1.5959	1.6807
1666	0	CORRELATION	-0.0355	1.6333	1.6688

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.091	-0.067625	-0.0355	0.02556	-0.2444	0.2511	1.6333	0.92193	-0.1534	0.31873	1.6688	0.90058
1e+12	-0.1355	-0.08875	-0.0692	0.031362	-0.1962	0.7525	1.6146	0.98781	-0.127	0.84125	1.7501	1.0062
5e+12	-0.2628	-0.10358	-0.0196	0.11119	-0.3193	0.27682	1.5523	0.87095	-0.1435	0.3804	1.5878	0.81322
1e+13	-0.1744	-0.11292	-0.0664	0.047987	-0.2649	0.34575	1.5959	0.8721	-0.1985	0.45867	1.6807	0.85667

Device Test: 19.19 CURRENT|EA//5/5/0/0/5/100kHz//@EA_IB





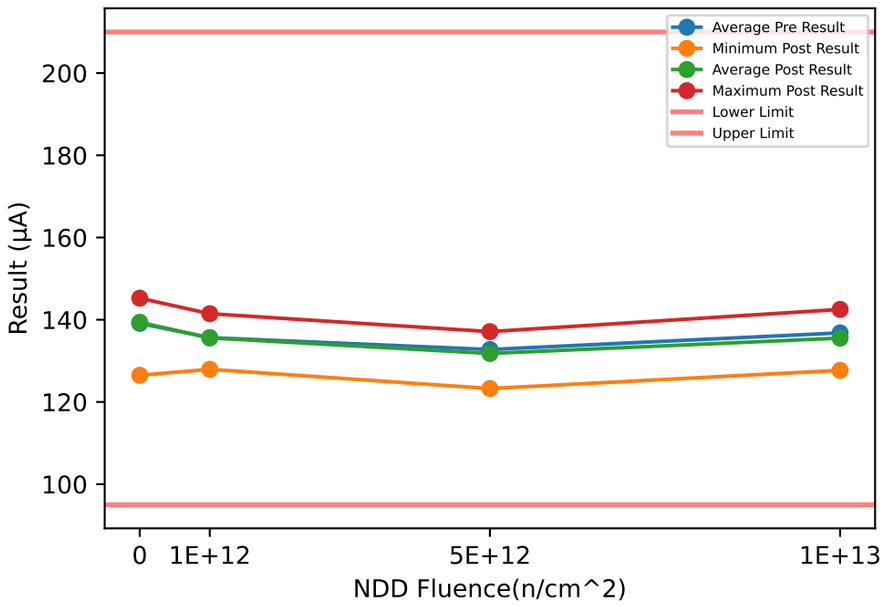
Test Results (Upper Limit = 25.0 (nA))

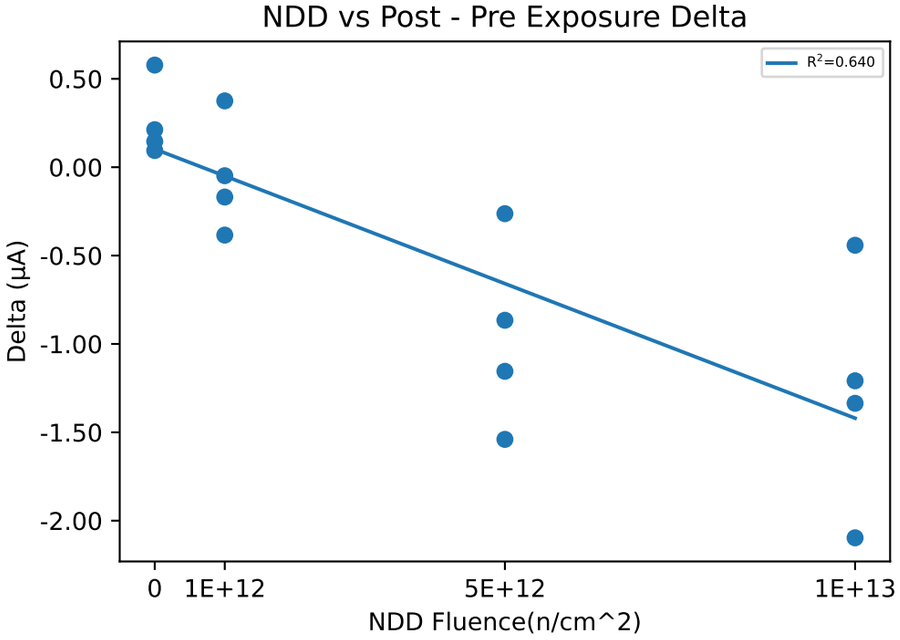
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.0633	-0.2257	-0.1624
466	1e+12	NDD	-0.0882	1.6489	1.7371
762	0	CORRELATION	-0.3191	-0.0106	0.3085
769	1e+12	NDD	-0.2667	1.6676	1.9343
887	1e+12	NDD	-0.266	-0.1869	0.0791
891	0	CORRELATION	-0.137	-0.2399	-0.1029
927	1e+12	NDD	-0.0964	0.3418	0.4382
967	5e+12	NDD	0.002	1.5429	1.5409
1204	1e+13	NDD	-0.0621	-0.2087	-0.1466
1284	1e+13	NDD	-0.0695	-0.2118	-0.1423
1292	5e+12	NDD	-0.1245	-0.2243	-0.0998
1364	1e+13	NDD	-0.1136	-0.3006	-0.187
1383	5e+12	NDD	-0.1723	-0.0324	0.1399
1388	5e+12	NDD	-0.057	0.2701	0.3271
1427	1e+13	NDD	-0.1972	1.5585	1.7557
1666	0	CORRELATION	-0.1792	1.4088	1.588

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.3191	-0.17465	-0.0633	0.10755	-0.2399	0.23315	1.4088	0.79076	-0.1624	0.4078	1.588	0.81418
1e+12	-0.2667	-0.17933	-0.0882	0.10054	-0.1869	0.86785	1.6676	0.93788	0.0791	1.0472	1.9343	0.92574
5e+12	-0.1723	-0.08795	0.002	0.076376	-0.2243	0.38908	1.5429	0.79568	-0.0998	0.47702	1.5409	0.73045
1e+13	-0.1972	-0.1106	-0.0621	0.062048	-0.3006	0.20935	1.5585	0.90044	-0.187	0.31995	1.7557	0.95738

Device Test: 19.2 CURRENT|EA_SOURCE//4.5/4.5/0/0/4.5/500kHz//@EA_I_SOURCE





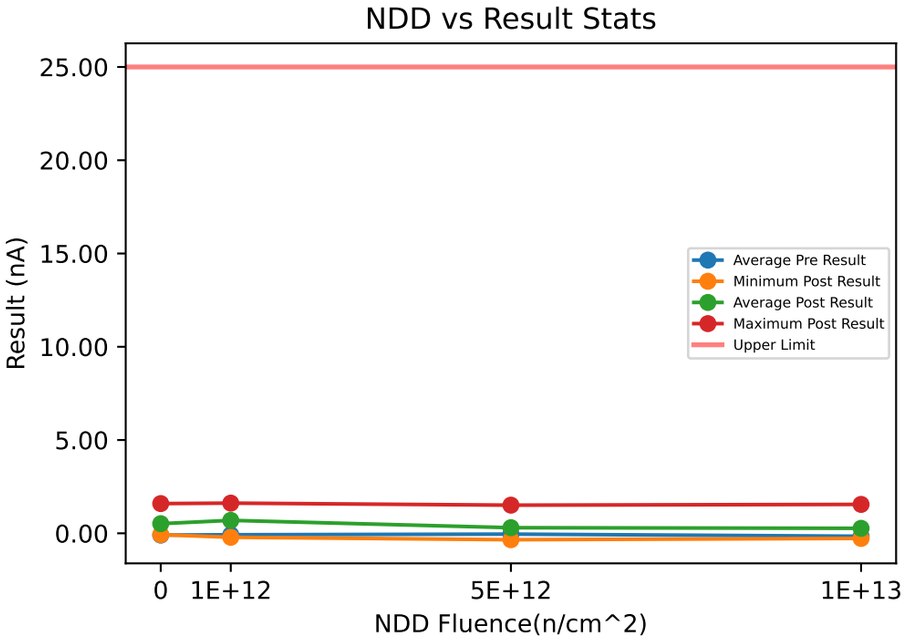
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

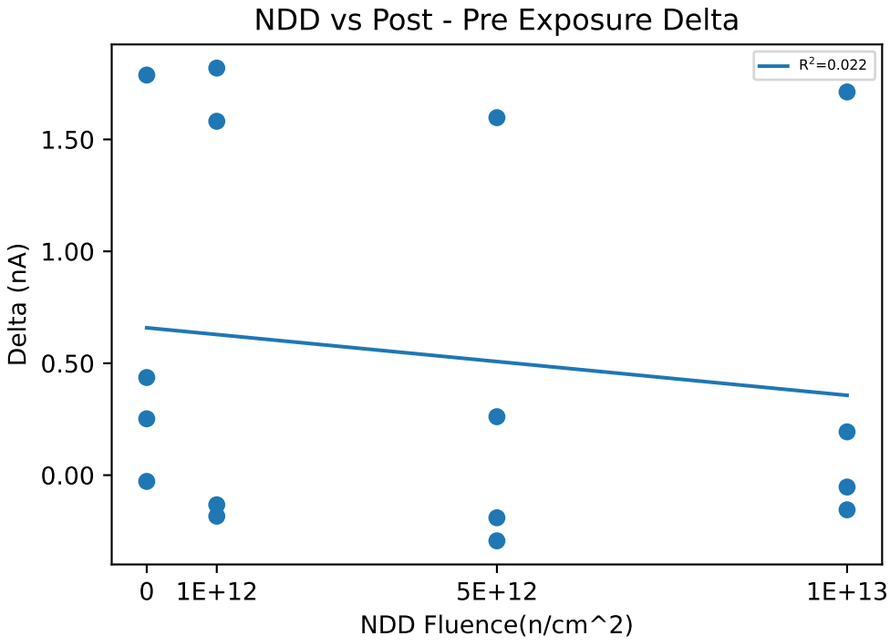
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	143.55	143.64	0.0945
466	1e+12	NDD	141.1	141.47	0.3753
762	0	CORRELATION	145.1	145.25	0.1457
769	1e+12	NDD	127.99	127.94	-0.0482
887	1e+12	NDD	135.55	135.17	-0.3841
891	0	CORRELATION	126.28	126.49	0.2124
927	1e+12	NDD	137.93	137.76	-0.1688
967	5e+12	NDD	137.97	137.11	-0.866
1204	1e+13	NDD	134.1	133.66	-0.4416
1284	1e+13	NDD	129.79	127.69	-2.097
1292	5e+12	NDD	136.11	134.57	-1.54
1364	1e+13	NDD	143.85	142.51	-1.3359
1383	5e+12	NDD	133.39	132.23	-1.1549
1388	5e+12	NDD	123.53	123.27	-0.2629
1427	1e+13	NDD	139.45	138.24	-1.2085
1666	0	CORRELATION	141.55	142.13	0.5779

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.28	139.12	145.1	8.6814	126.49	139.38	145.25	8.683	0.0945	0.25762	0.5779	0.21891
1e+12	127.99	135.64	141.1	5.5861	127.94	135.59	141.47	5.7169	-0.3841	-0.05645	0.3753	0.31961
5e+12	123.53	132.75	137.97	6.4276	123.27	131.8	137.11	6.0221	-1.54	-0.95595	-0.2629	0.53824
1e+13	129.79	136.8	143.85	6.1412	127.69	135.52	142.51	6.3521	-2.097	-1.2708	-0.4416	0.67781

Device Test: 19.20 CURRENT|EA//5/5/0/0/5/1MHz//@EA_IB





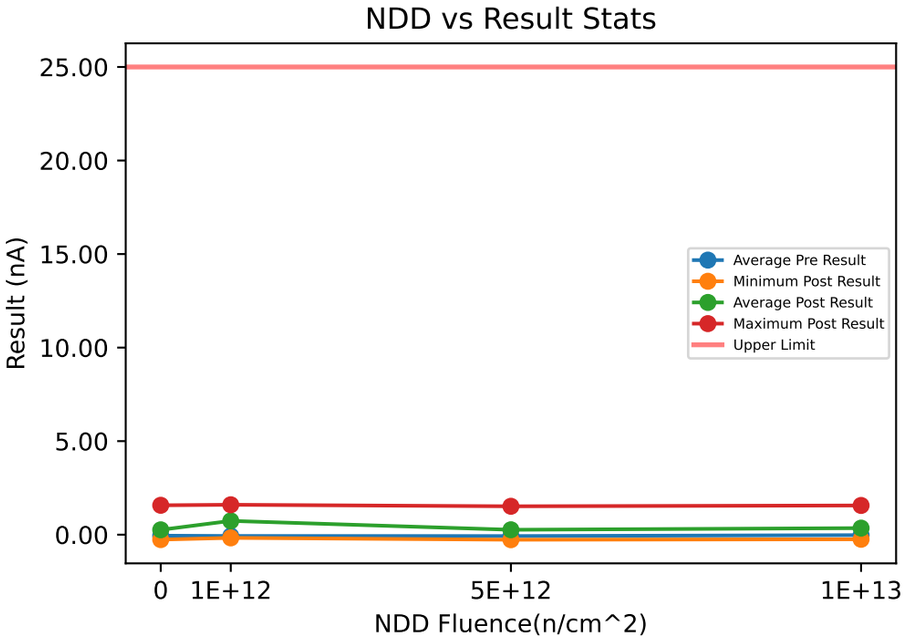
Test Results (Upper Limit = 25.0 (nA))

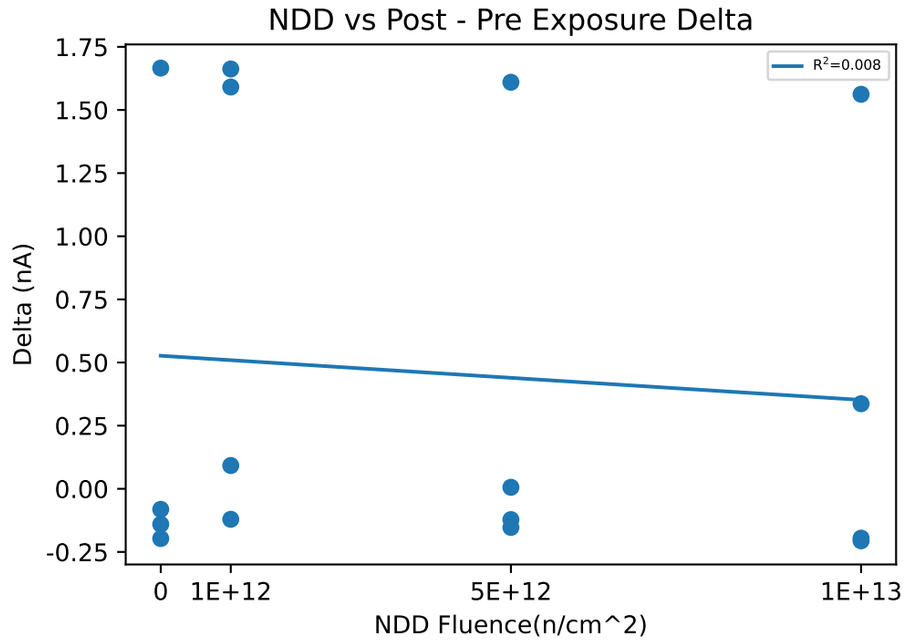
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.1194	0.3168	0.4362
466	1e+12	NDD	-0.0476	1.5335	1.5811
762	0	CORRELATION	-0.0223	0.2295	0.2518
769	1e+12	NDD	-0.2011	1.6177	1.8188
887	1e+12	NDD	0.0183	-0.165	-0.1833
891	0	CORRELATION	-0.0465	-0.0744	-0.0279
927	1e+12	NDD	-0.0808	-0.2132	-0.1324
967	5e+12	NDD	-0.0886	1.5086	1.5972
1204	1e+13	NDD	-0.2212	-0.2743	-0.0531
1284	1e+13	NDD	-0.0789	-0.2337	-0.1548
1292	5e+12	NDD	-0.0714	-0.2618	-0.1904
1364	1e+13	NDD	-0.1667	0.0268	0.1935
1383	5e+12	NDD	0.037	0.2981	0.2611
1388	5e+12	NDD	-0.0508	-0.3442	-0.2934
1427	1e+13	NDD	-0.1629	1.5491	1.712
1666	0	CORRELATION	-0.1949	1.5928	1.7877

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1949	-0.095775	-0.0223	0.077911	-0.0744	0.51618	1.5928	0.73707	-0.0279	0.61195	1.7877	0.80672
1e+12	-0.2011	-0.0778	0.0183	0.09194	-0.2132	0.69325	1.6177	1.0196	-0.1833	0.77105	1.8188	1.0772
5e+12	-0.0886	-0.04345	0.037	0.055815	-0.3442	0.30017	1.5086	0.85466	-0.2934	0.34363	1.5972	0.86972
1e+13	-0.2212	-0.15742	-0.0789	0.058735	-0.2743	0.26697	1.5491	0.8651	-0.1548	0.4244	1.712	0.87077

Device Test: 19.21 CURRENT|EA//12/12/0/0/5/100kHz//@EA_IB





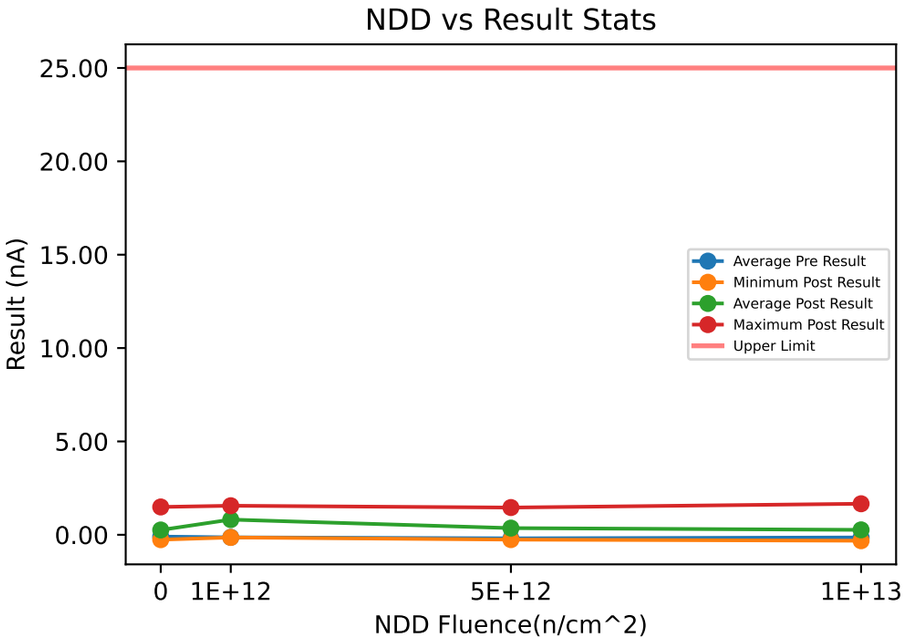
Test Results (Upper Limit = 25.0 (nA))

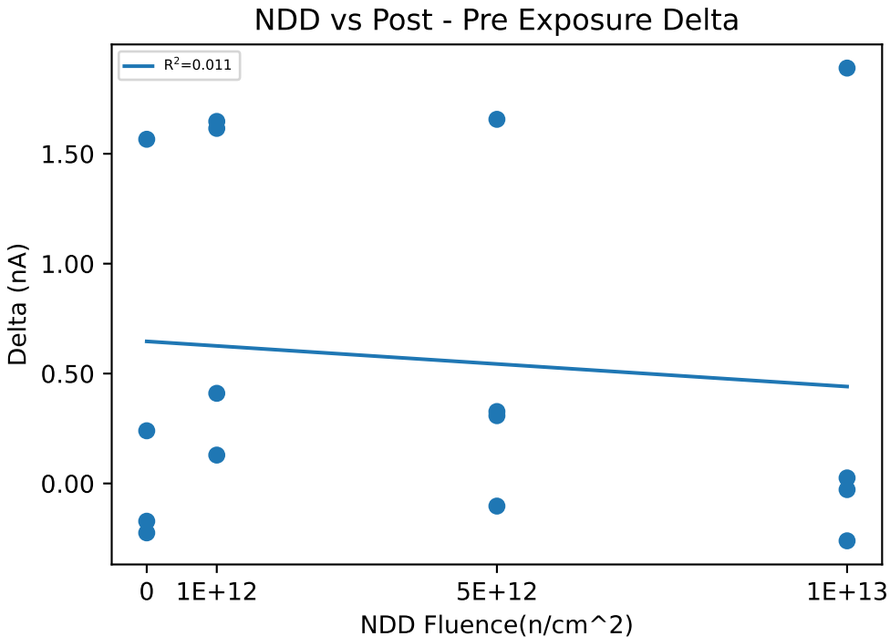
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0054	-0.076	-0.0814
466	1e+12	NDD	-0.0633	1.599	1.6623
762	0	CORRELATION	-0.0661	-0.2631	-0.197
769	1e+12	NDD	-0.0667	1.5242	1.5909
887	1e+12	NDD	-0.0504	-0.1712	-0.1208
891	0	CORRELATION	-0.0527	-0.1931	-0.1404
927	1e+12	NDD	-0.0933	-0.0012	0.0921
967	5e+12	NDD	-0.0917	1.518	1.6097
1204	1e+13	NDD	-0.0402	-0.2462	-0.206
1284	1e+13	NDD	-0.0071	-0.2025	-0.1954
1292	5e+12	NDD	-0.0808	-0.2337	-0.1529
1364	1e+13	NDD	-0.048	0.2888	0.3368
1383	5e+12	NDD	-0.1473	-0.2694	-0.1221
1388	5e+12	NDD	0.0272	0.0331	0.0059
1427	1e+13	NDD	-0.0005	1.5616	1.5621
1666	0	CORRELATION	-0.0949	1.571	1.6659

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.0949	-0.052075	0.0054	0.042168	-0.2631	0.2597	1.571	0.8776	-0.197	0.31177	1.6659	0.90398
1e+12	-0.0933	-0.068425	-0.0504	0.018008	-0.1712	0.7377	1.599	0.95437	-0.1208	0.80612	1.6623	0.95183
5e+12	-0.1473	-0.07315	0.0272	0.072963	-0.2694	0.262	1.518	0.84814	-0.1529	0.33515	1.6097	0.85248
1e+13	-0.048	-0.02395	-0.0005	0.023638	-0.2462	0.35042	1.5616	0.8431	-0.206	0.37438	1.5621	0.83138

Device Test: 19.22 CURRENT|EA//12/12/0/0/5/1MHz//@EA_IB





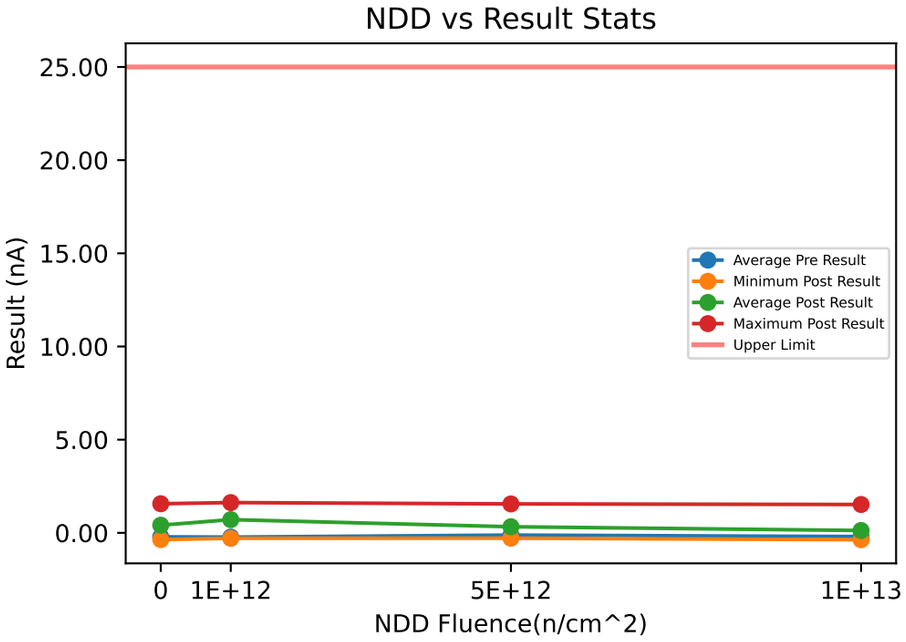
Test Results (Upper Limit = 25.0 (nA))

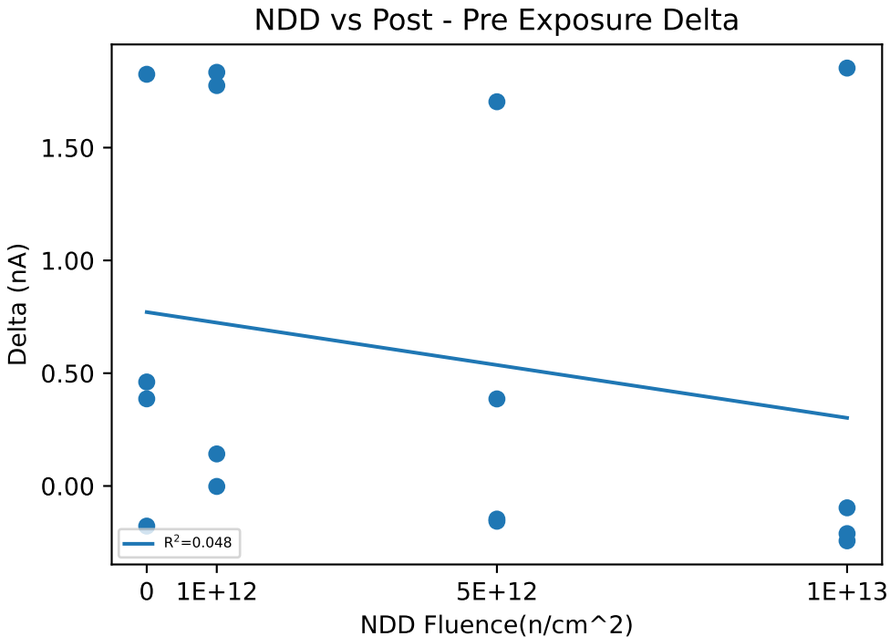
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.0633	-0.2351	-0.1718
466	1e+12	NDD	-0.0601	1.5554	1.6155
762	0	CORRELATION	-0.2066	0.0331	0.2397
769	1e+12	NDD	-0.1355	1.5117	1.6472
887	1e+12	NDD	-0.2722	-0.1431	0.1291
891	0	CORRELATION	-0.0371	-0.2618	-0.2247
927	1e+12	NDD	-0.0808	0.3293	0.4101
967	5e+12	NDD	-0.198	1.4587	1.6567
1204	1e+13	NDD	-0.1557	-0.1837	-0.028
1284	1e+13	NDD	-0.057	-0.318	-0.261
1292	5e+12	NDD	-0.1557	-0.2587	-0.103
1364	1e+13	NDD	-0.1324	-0.1072	0.0252
1383	5e+12	NDD	-0.3565	-0.0293	0.3272
1388	5e+12	NDD	-0.0508	0.2576	0.3084
1427	1e+13	NDD	-0.2285	1.6614	1.8899
1666	0	CORRELATION	-0.0761	1.4899	1.566

Test Statistics (nA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2066	-0.095775	-0.0371	0.075645	-0.2618	0.25653	1.4899	0.83296	-0.2247	0.3523	1.566	0.83534
1e+12	-0.2722	-0.13715	-0.0601	0.095487	-0.1431	0.81332	1.5554	0.8539	0.1291	0.95047	1.6472	0.79464
5e+12	-0.3565	-0.19025	-0.0508	0.12694	-0.2587	0.35708	1.4587	0.76419	-0.103	0.54733	1.6567	0.76576
1e+13	-0.2285	-0.1434	-0.057	0.070662	-0.318	0.26312	1.6614	0.93625	-0.261	0.40652	1.8899	0.9967

Device Test: 19.23 CURRENT|EA//14/14/0/0/5/100kHz//@EA_IB





Test Results (Upper Limit = 25.0 (nA))

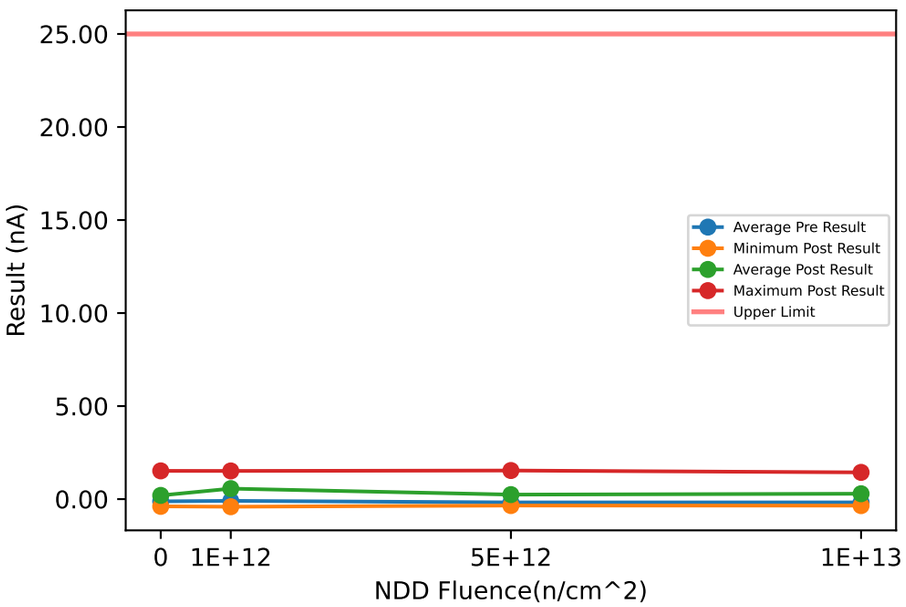
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.1569	0.2295	0.3864
466	1e+12	NDD	-0.2099	1.624	1.8339
762	0	CORRELATION	-0.2503	0.2108	0.4611
769	1e+12	NDD	-0.2042	1.571	1.7752
887	1e+12	NDD	-0.291	-0.293	-0.002
891	0	CORRELATION	-0.1838	-0.3617	-0.1779
927	1e+12	NDD	-0.2088	-0.0667	0.1421
967	5e+12	NDD	-0.1511	1.5523	1.7034
1204	1e+13	NDD	-0.1869	-0.2837	-0.0968
1284	1e+13	NDD	-0.1537	-0.3649	-0.2112
1292	5e+12	NDD	-0.1401	-0.2868	-0.1467
1364	1e+13	NDD	-0.1261	-0.3692	-0.2431
1383	5e+12	NDD	-0.091	0.295	0.386
1388	5e+12	NDD	-0.0976	-0.2538	-0.1562
1427	1e+13	NDD	-0.3316	1.5211	1.8527
1666	0	CORRELATION	-0.2636	1.5616	1.8252

Test Statistics (nA)

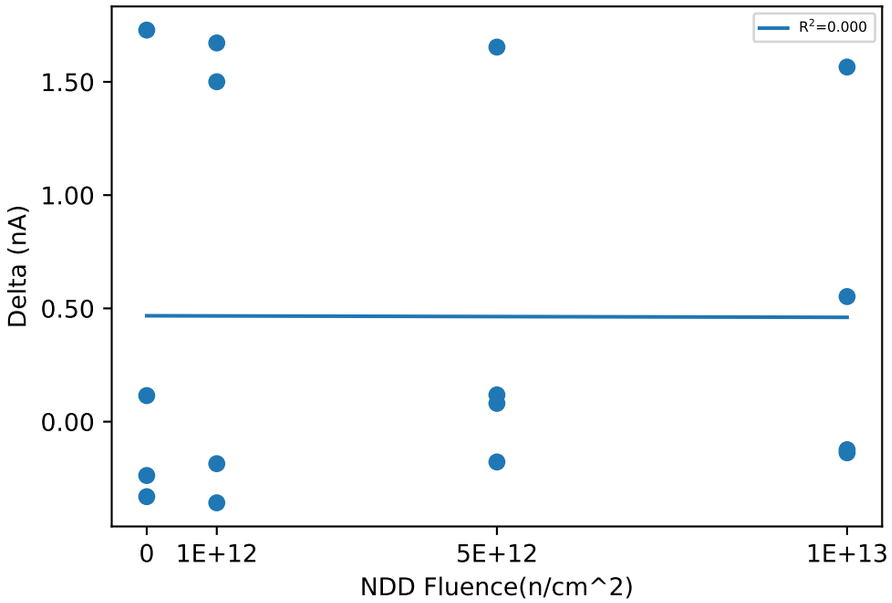
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2636	-0.21365	-0.1569	0.051478	-0.3617	0.41005	1.5616	0.81526	-0.1779	0.6237	1.8252	0.85028
1e+12	-0.291	-0.22847	-0.2042	0.041756	-0.293	0.70883	1.624	1.0305	-0.002	0.9373	1.8339	1.0034
5e+12	-0.1511	-0.11995	-0.091	0.030078	-0.2868	0.32667	1.5523	0.85955	-0.1562	0.44662	1.7034	0.87533
1e+13	-0.3316	-0.19958	-0.1261	0.091459	-0.3692	0.12582	1.5211	0.93101	-0.2431	0.3254	1.8527	1.0201

Device Test: 19.24 CURRENT|EA//14/14/0/0/5/1MHz//@EA_IB

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 25.0 (nA))

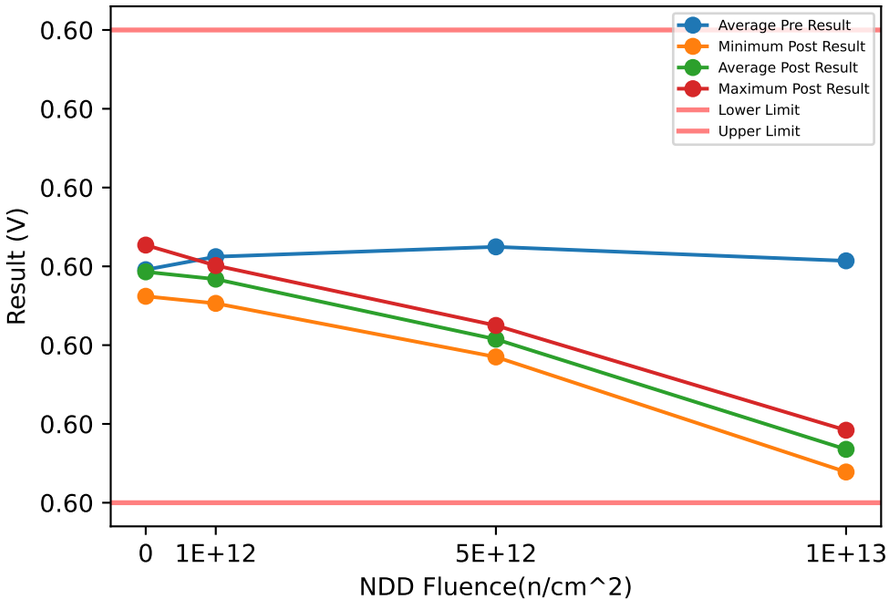
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.1569	-0.0418	0.1151
466	1e+12	NDD	-0.1569	1.5148	1.6717
762	0	CORRELATION	-0.0536	-0.2912	-0.2376
769	1e+12	NDD	-0.0043	1.4961	1.5004
887	1e+12	NDD	-0.0504	-0.4086	-0.3582
891	0	CORRELATION	-0.0589	-0.3899	-0.331
927	1e+12	NDD	-0.1619	-0.3473	-0.1854
967	5e+12	NDD	-0.1167	1.5367	1.6534
1204	1e+13	NDD	-0.2119	-0.3493	-0.1374
1284	1e+13	NDD	-0.16	-0.2837	-0.1237
1292	5e+12	NDD	-0.1682	-0.3461	-0.1779
1364	1e+13	NDD	-0.2011	0.3511	0.5522
1383	5e+12	NDD	-0.241	-0.1602	0.0808
1388	5e+12	NDD	-0.1787	-0.0605	0.1182
1427	1e+13	NDD	-0.1285	1.4369	1.5654
1666	0	CORRELATION	-0.2105	1.518	1.7285

Test Statistics (nA)

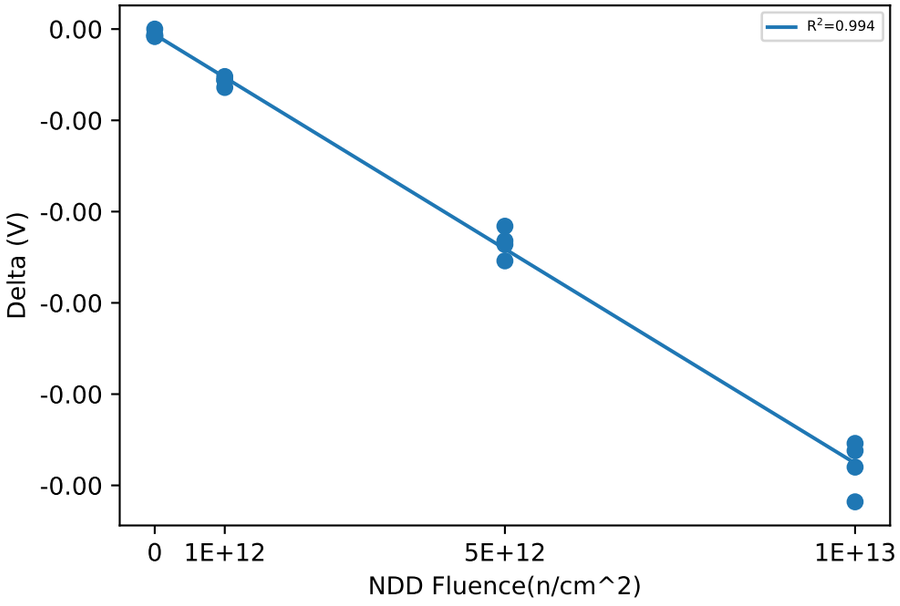
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.2105	-0.11997	-0.0536	0.076798	-0.3899	0.19877	1.518	0.8916	-0.331	0.31875	1.7285	0.95927
1e+12	-0.1619	-0.093375	-0.0043	0.078554	-0.4086	0.56375	1.5148	1.0877	-0.3582	0.65712	1.6717	1.0772
5e+12	-0.241	-0.17615	-0.1167	0.051021	-0.3461	0.24247	1.5367	0.8709	-0.1779	0.41862	1.6534	0.83365
1e+13	-0.2119	-0.17538	-0.1285	0.038425	-0.3493	0.28875	1.4369	0.82804	-0.1374	0.46413	1.5654	0.80165

Device Test: 19.25 VOLTAGE|VREF//4.5/4.5/0/0/4.5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

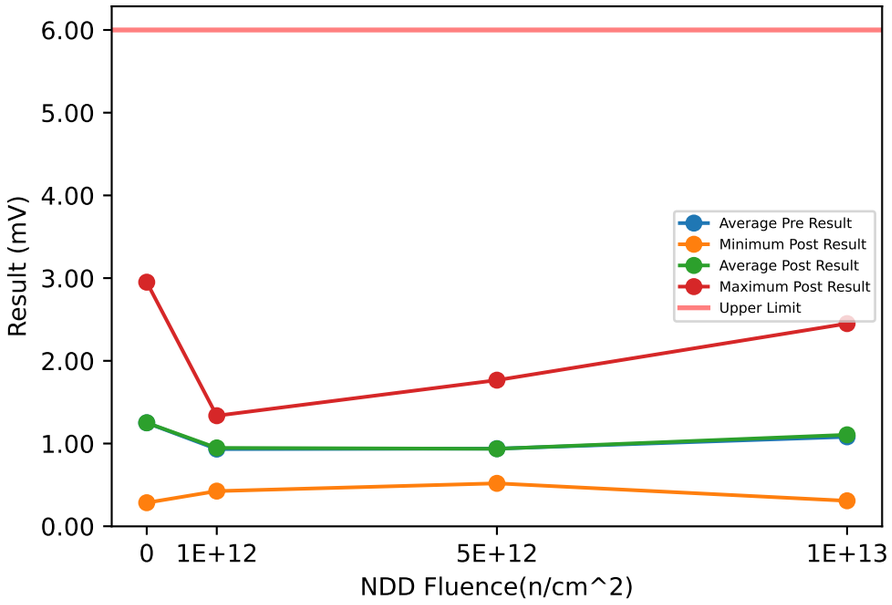
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60013	0.60009	-4e-05
466	1e+12	NDD	0.6001	0.59982	-0.00028
762	0	CORRELATION	0.59965	0.59962	-3e-05
769	1e+12	NDD	0.59979	0.59953	-0.00026
887	1e+12	NDD	0.60033	0.60001	-0.00032
891	0	CORRELATION	0.59974	0.59974	0
927	1e+12	NDD	0.60027	0.59999	-0.00028
967	5e+12	NDD	0.60012	0.59885	-0.00127
1204	1e+13	NDD	0.60007	0.59767	-0.0024
1284	1e+13	NDD	0.5997	0.59739	-0.00231
1292	5e+12	NDD	0.60034	0.59918	-0.00116
1364	1e+13	NDD	0.60032	0.59773	-0.00259
1383	5e+12	NDD	0.60033	0.59925	-0.00108
1388	5e+12	NDD	0.6002	0.59902	-0.00118
1427	1e+13	NDD	0.60019	0.59792	-0.00227
1666	0	CORRELATION	0.60031	0.60027	-4e-05

Test Statistics (V)

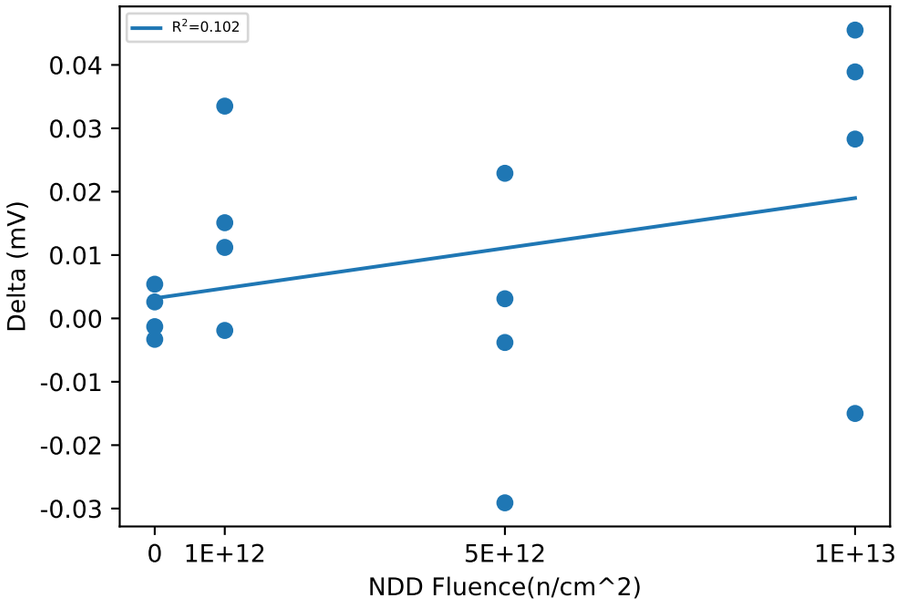
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59965	0.59996	0.60031	0.00031405	0.59962	0.59993	0.60027	0.00030188	-4e-05	-2.75e-05	0	1.893e-05
1e+12	0.59979	0.60012	0.60033	0.00024213	0.59953	0.59984	0.60001	0.00022202	-0.00032	-0.000285	-0.00026	2.5166e-05
5e+12	0.60012	0.60025	0.60034	0.00010626	0.59885	0.59908	0.59925	0.00017823	-0.00127	-0.0011725	-0.00108	7.8049e-05
1e+13	0.5997	0.60007	0.60032	0.00026696	0.59739	0.59768	0.59792	0.0002193	-0.00259	-0.0023925	-0.00227	0.00014245

Device Test: 19.27 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/100kHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

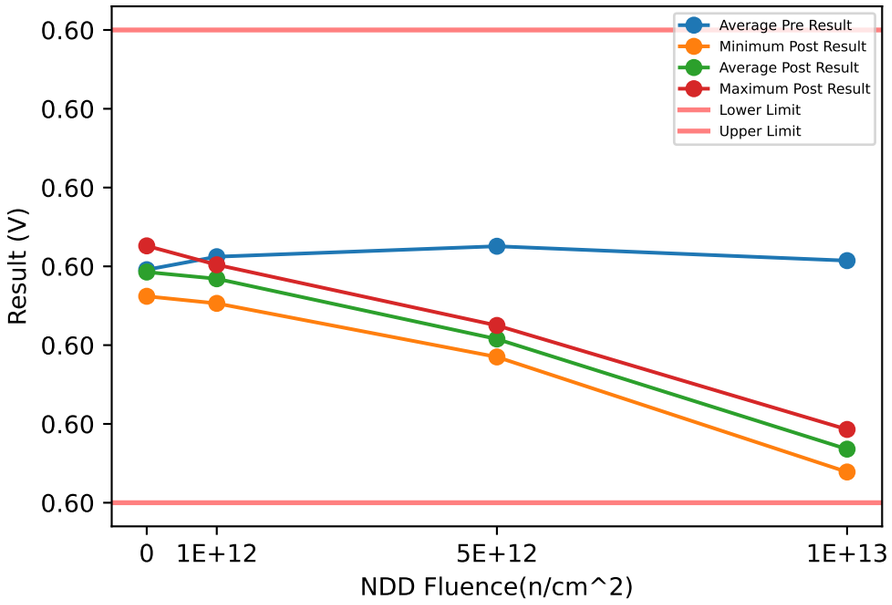
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.9482	2.9508	0.0026
466	1e+12	NDD	1.3241	1.3222	-0.0019
762	0	CORRELATION	0.2878	0.2845	-0.0033
769	1e+12	NDD	0.6906	0.7057	0.0151
887	1e+12	NDD	1.3252	1.3364	0.0112
891	0	CORRELATION	1.1267	1.1321	0.0054
927	1e+12	NDD	0.3914	0.4249	0.0335
967	5e+12	NDD	0.5224	0.5186	-0.0038
1204	1e+13	NDD	0.3229	0.3079	-0.015
1284	1e+13	NDD	0.4027	0.4482	0.0455
1292	5e+12	NDD	0.8669	0.87	0.0031
1364	1e+13	NDD	1.1769	1.2158	0.0389
1383	5e+12	NDD	1.7433	1.7662	0.0229
1388	5e+12	NDD	0.6203	0.5912	-0.0291
1427	1e+13	NDD	2.4217	2.45	0.0283
1666	0	CORRELATION	0.639	0.6377	-0.0013

Test Statistics (mV)

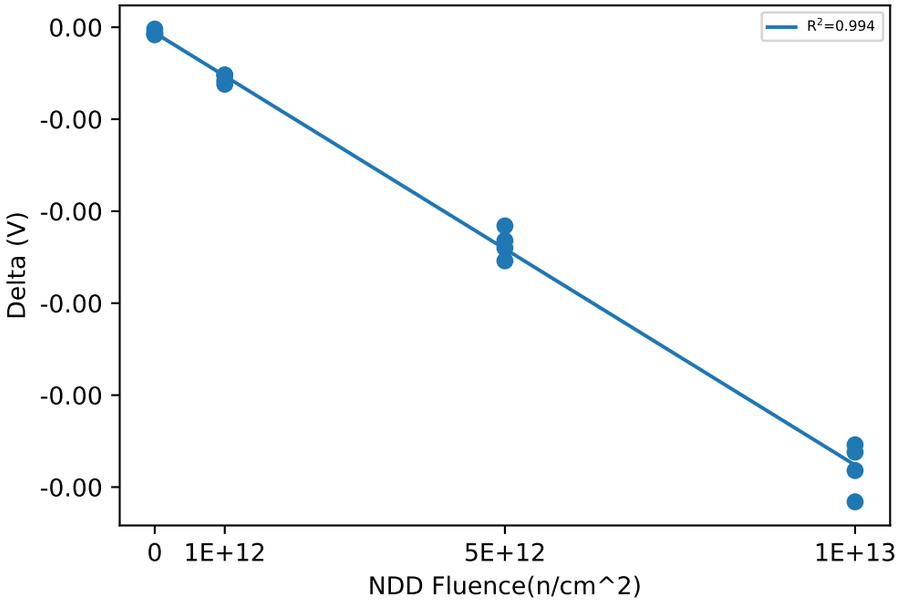
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2878	1.2504	2.9482	1.183	0.2845	1.2513	2.9508	1.1851	-0.0033	0.00085	0.0054	0.0038991
1e+12	0.3914	0.93283	1.3252	0.46864	0.4249	0.9473	1.3364	0.45579	-0.0019	0.014475	0.0335	0.01462
5e+12	0.5224	0.93822	1.7433	0.55594	0.5186	0.9365	1.7662	0.5735	-0.0291	-0.001725	0.0229	0.021474
1e+13	0.3229	1.0811	2.4217	0.97322	0.3079	1.1055	2.45	0.98117	-0.015	0.024425	0.0455	0.027221

Device Test: 19.28 VOLTAGE|VREF//5/5/0/0/5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

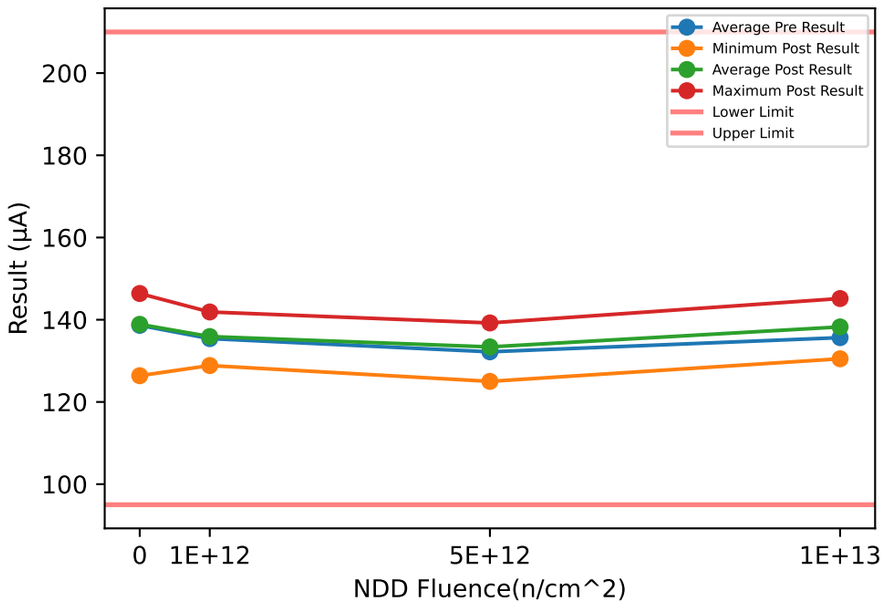
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60014	0.6001	-4e-05
466	1e+12	NDD	0.60011	0.59982	-0.00029
762	0	CORRELATION	0.59965	0.59962	-3e-05
769	1e+12	NDD	0.59979	0.59953	-0.00026
887	1e+12	NDD	0.60033	0.60002	-0.00031
891	0	CORRELATION	0.59974	0.59973	-1e-05
927	1e+12	NDD	0.60026	0.6	-0.00026
967	5e+12	NDD	0.60012	0.59885	-0.00127
1204	1e+13	NDD	0.60007	0.59766	-0.00241
1284	1e+13	NDD	0.5997	0.59739	-0.00231
1292	5e+12	NDD	0.60035	0.59919	-0.00116
1364	1e+13	NDD	0.60032	0.59774	-0.00258
1383	5e+12	NDD	0.60033	0.59925	-0.00108
1388	5e+12	NDD	0.60022	0.59902	-0.0012
1427	1e+13	NDD	0.6002	0.59793	-0.00227
1666	0	CORRELATION	0.6003	0.60026	-4e-05

Test Statistics (V)

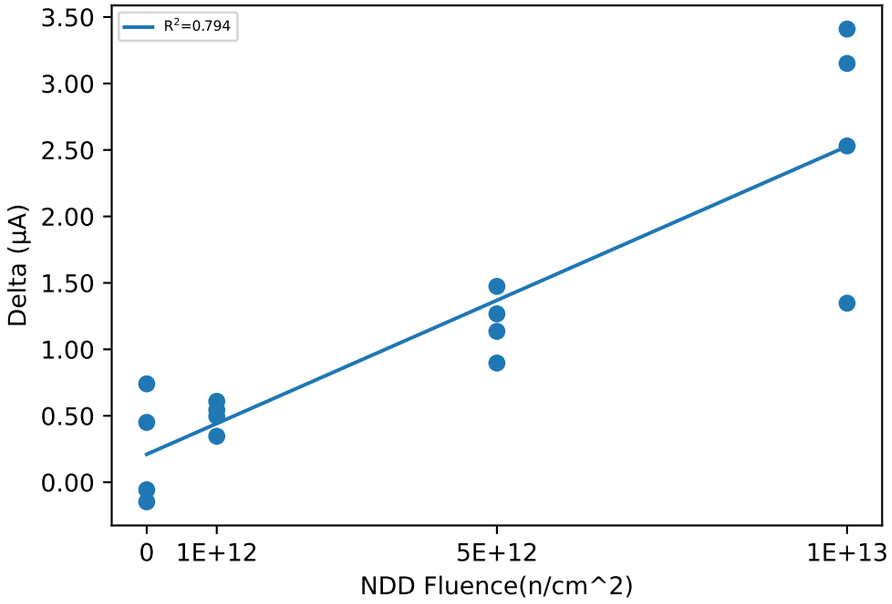
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59965	0.59996	0.6003	0.00031224	0.59962	0.59993	0.60026	0.00030215	-4e-05	-3e-05	-1e-05	1.4142e-05
1e+12	0.59979	0.60012	0.60033	0.00023991	0.59953	0.59984	0.60002	0.00022692	-0.00031	-0.00028	-0.00026	2.4495e-05
5e+12	0.60012	0.60025	0.60035	0.00010661	0.59885	0.59908	0.59925	0.00018025	-0.00127	-0.0011775	-0.00108	7.932e-05
1e+13	0.5997	0.60007	0.60032	0.0002685	0.59739	0.59768	0.59793	0.00022405	-0.00258	-0.0023925	-0.00227	0.00013817

Device Test: 19.3 CURRENT|EA_SINK//4.5/4.5/0/0/4.5/500kHz//@EA_I_SINK

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



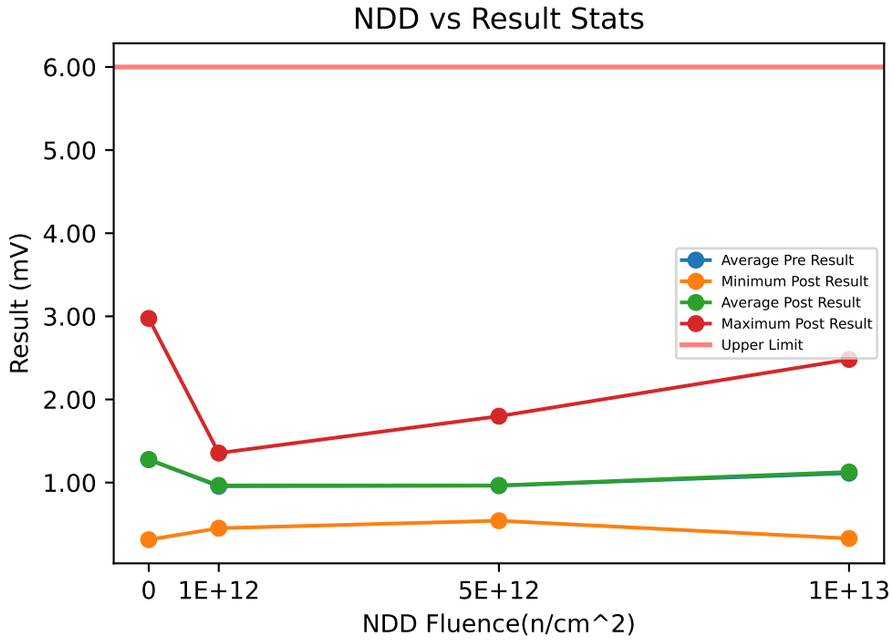
Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

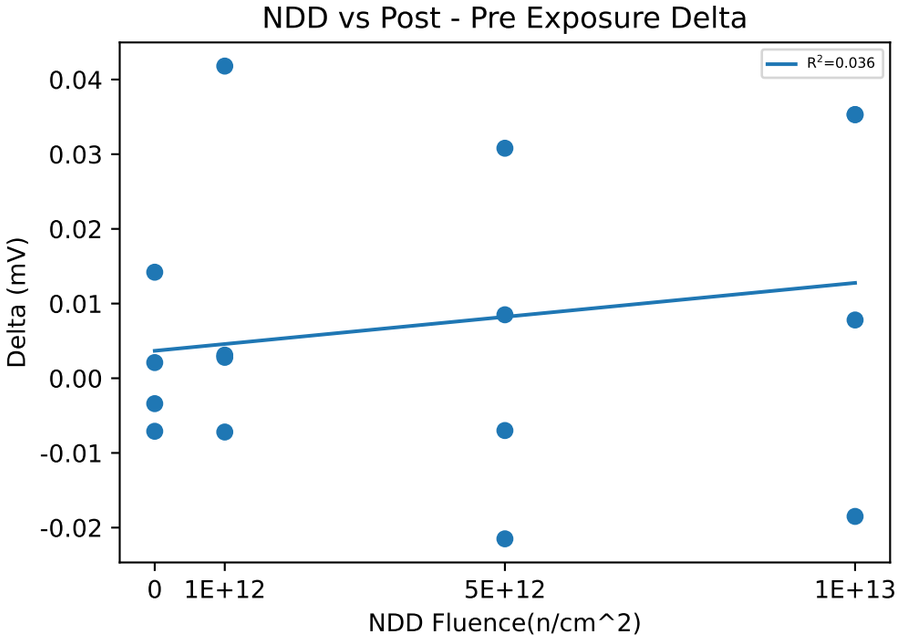
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	141.85	141.79	-0.0565
466	1e+12	NDD	141.34	141.89	0.5445
762	0	CORRELATION	145.64	146.38	0.7404
769	1e+12	NDD	128.25	128.86	0.6091
887	1e+12	NDD	134.08	134.43	0.3463
891	0	CORRELATION	126.53	126.38	-0.1471
927	1e+12	NDD	137.96	138.46	0.497
967	5e+12	NDD	137.95	139.22	1.2672
1204	1e+13	NDD	133.82	137.23	3.4094
1284	1e+13	NDD	129.15	130.5	1.3475
1292	5e+12	NDD	135.61	136.5	0.8968
1364	1e+13	NDD	142	145.15	3.1509
1383	5e+12	NDD	131.7	132.83	1.1352
1388	5e+12	NDD	123.53	125	1.4736
1427	1e+13	NDD	137.6	140.13	2.5303
1666	0	CORRELATION	140.53	140.98	0.4504

Test Statistics (µA)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.53	138.64	145.64	8.3563	126.38	138.88	146.38	8.6658	-0.1471	0.2468	0.7404	0.42121
1e+12	128.25	135.41	141.34	5.6207	128.86	135.91	141.89	5.6027	0.3463	0.49922	0.6091	0.11182
5e+12	123.53	132.2	137.95	6.3282	125	133.39	139.22	6.1736	0.8968	1.1932	1.4736	0.24174
1e+13	129.15	135.64	142	5.4694	130.5	138.25	145.15	6.1186	1.3475	2.6095	3.4094	0.91867

Device Test: 19.30 VOLTAGE|OFFSET//5/5/0/0/5/100kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

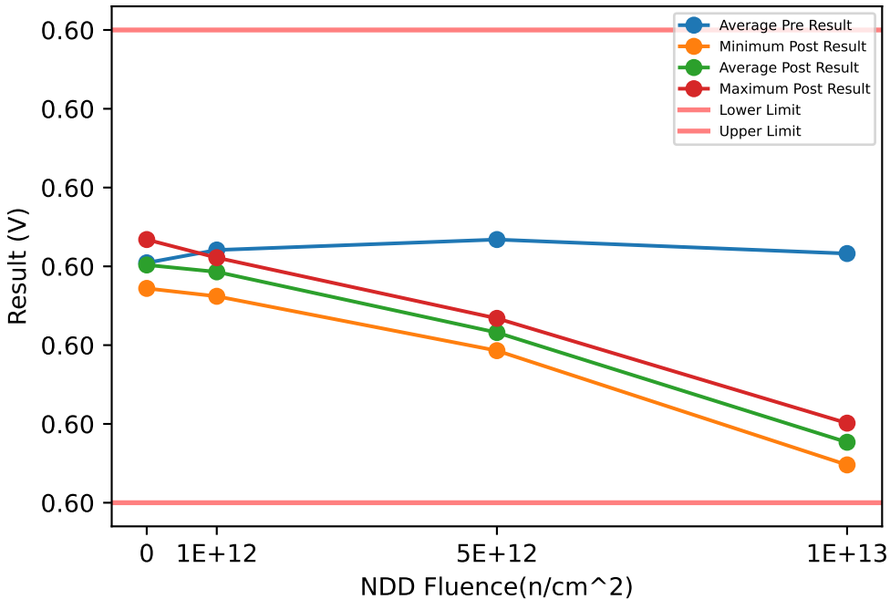
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.9821	2.975	-0.0071
466	1e+12	NDD	1.3475	1.3403	-0.0072
762	0	CORRELATION	0.3103	0.3124	0.0021
769	1e+12	NDD	0.7134	0.7162	0.0028
887	1e+12	NDD	1.3519	1.355	0.0031
891	0	CORRELATION	1.1494	1.1636	0.0142
927	1e+12	NDD	0.4091	0.4509	0.0418
967	5e+12	NDD	0.5479	0.5409	-0.007
1204	1e+13	NDD	0.3461	0.3276	-0.0185
1284	1e+13	NDD	0.4305	0.4658	0.0353
1292	5e+12	NDD	0.8952	0.9037	0.0085
1364	1e+13	NDD	1.2007	1.236	0.0353
1383	5e+12	NDD	1.7677	1.7985	0.0308
1388	5e+12	NDD	0.6399	0.6184	-0.0215
1427	1e+13	NDD	2.4739	2.4817	0.0078
1666	0	CORRELATION	0.6608	0.6574	-0.0034

Test Statistics (mV)

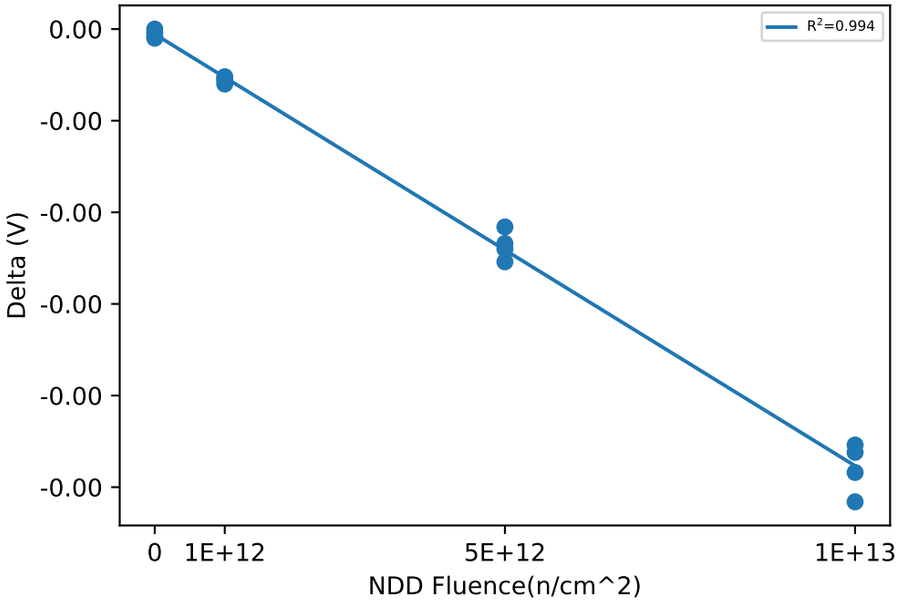
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3103	1.2756	2.9821	1.1885	0.3124	1.2771	2.975	1.1847	-0.0071	0.00145	0.0142	0.0093025
1e+12	0.4091	0.95548	1.3519	0.47186	0.4509	0.9656	1.355	0.45429	-0.0072	0.010125	0.0418	0.021652
5e+12	0.5479	0.96268	1.7677	0.55643	0.5409	0.96537	1.7985	0.57691	-0.0215	0.0027	0.0308	0.022383
1e+13	0.3461	1.1128	2.4739	0.98551	0.3276	1.1278	2.4817	0.98714	-0.0185	0.014975	0.0353	0.025809

Device Test: 19.31 VOLTAGE|VREF//12/12/0/0/5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

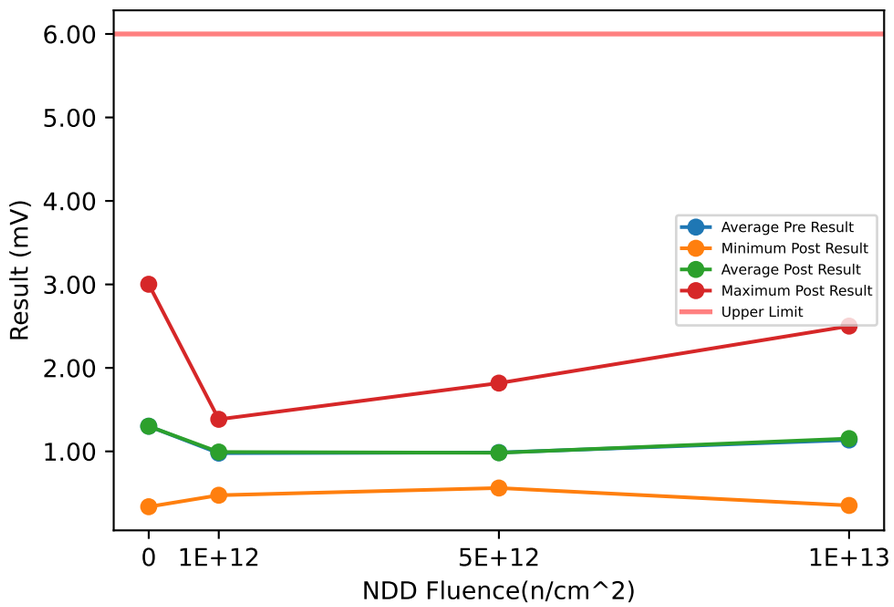
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60024	0.60019	-5e-05
466	1e+12	NDD	0.60019	0.59991	-0.00028
762	0	CORRELATION	0.59974	0.59972	-2e-05
769	1e+12	NDD	0.59988	0.59962	-0.00026
887	1e+12	NDD	0.60041	0.60011	-0.0003
891	0	CORRELATION	0.59982	0.59982	0
927	1e+12	NDD	0.60035	0.60008	-0.00027
967	5e+12	NDD	0.6002	0.59893	-0.00127
1204	1e+13	NDD	0.60017	0.59775	-0.00242
1284	1e+13	NDD	0.59979	0.59748	-0.00231
1292	5e+12	NDD	0.60044	0.59927	-0.00117
1364	1e+13	NDD	0.60041	0.59783	-0.00258
1383	5e+12	NDD	0.60042	0.59934	-0.00108
1388	5e+12	NDD	0.6003	0.5991	-0.0012
1427	1e+13	NDD	0.60028	0.59801	-0.00227
1666	0	CORRELATION	0.60038	0.60034	-4e-05

Test Statistics (V)

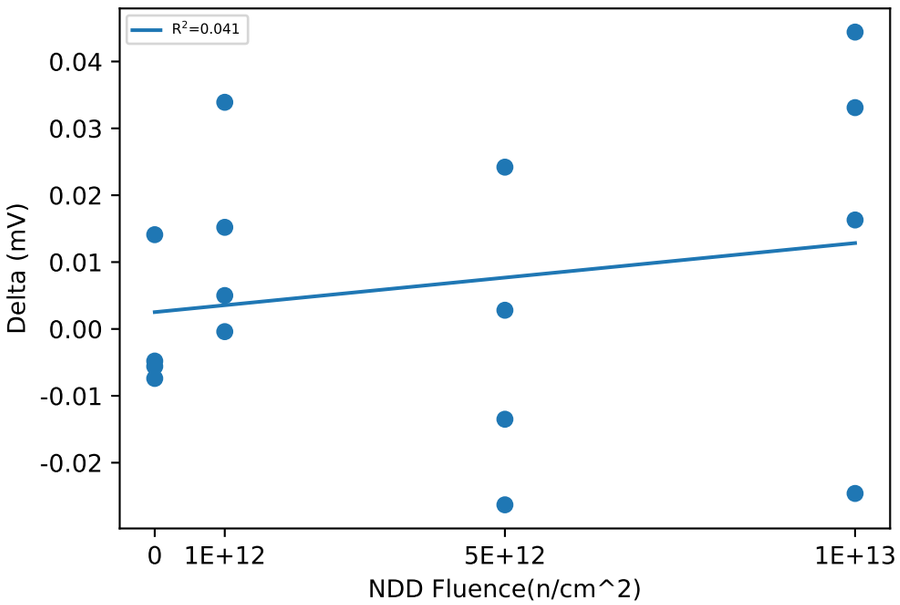
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59974	0.60005	0.60038	0.000313	0.59972	0.60002	0.60034	0.00029511	-5e-05	-2.75e-05	0	2.2174e-05
1e+12	0.59988	0.60021	0.60041	0.00023726	0.59962	0.59993	0.60011	0.00022465	-0.0003	-0.0002775	-0.00026	1.7078e-05
5e+12	0.6002	0.60034	0.60044	0.00011195	0.59893	0.59916	0.59934	0.00018348	-0.00127	-0.00118	-0.00108	7.874e-05
1e+13	0.59979	0.60016	0.60041	0.000267	0.59748	0.59777	0.59801	0.00022036	-0.00258	-0.002395	-0.00227	0.00013868

Device Test: 19.33 VOLTAGE|OFFSET//12/12/0/0/5/100kHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

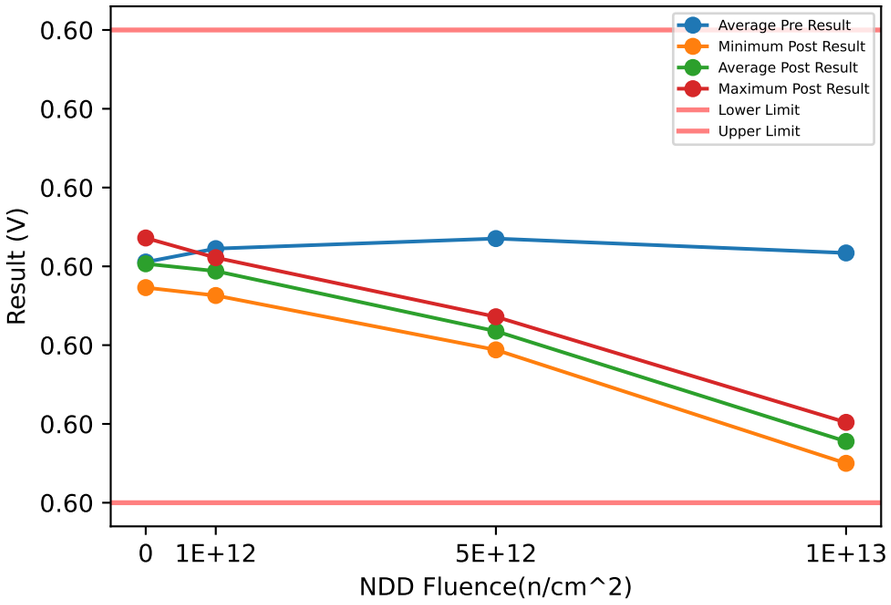
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.0093	3.0019	-0.0074
466	1e+12	NDD	1.3632	1.3628	-0.0004
762	0	CORRELATION	0.3419	0.3371	-0.0048
769	1e+12	NDD	0.7427	0.7477	0.005
887	1e+12	NDD	1.3689	1.3841	0.0152
891	0	CORRELATION	1.1717	1.1858	0.0141
927	1e+12	NDD	0.4408	0.4747	0.0339
967	5e+12	NDD	0.5746	0.5611	-0.0135
1204	1e+13	NDD	0.377	0.3524	-0.0246
1284	1e+13	NDD	0.4539	0.4983	0.0444
1292	5e+12	NDD	0.9154	0.9182	0.0028
1364	1e+13	NDD	1.2286	1.2617	0.0331
1383	5e+12	NDD	1.7936	1.8178	0.0242
1388	5e+12	NDD	0.6622	0.6359	-0.0263
1427	1e+13	NDD	2.4845	2.5008	0.0163
1666	0	CORRELATION	0.6844	0.6788	-0.0056

Test Statistics (mV)

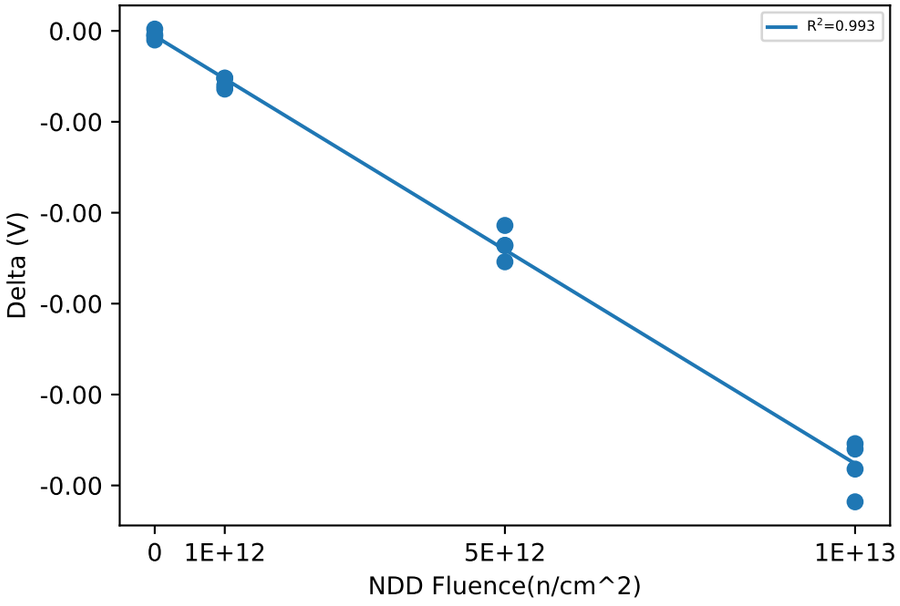
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3419	1.3018	3.0093	1.1881	0.3371	1.3009	3.0019	1.1864	-0.0074	-0.000925	0.0141	0.010076
1e+12	0.4408	0.9789	1.3689	0.46373	0.4747	0.99233	1.3841	0.45406	-0.0004	0.013425	0.0339	0.015105
5e+12	0.5746	0.98645	1.7936	0.55716	0.5611	0.98325	1.8178	0.57723	-0.0263	-0.0032	0.0242	0.021806
1e+13	0.377	1.136	2.4845	0.97782	0.3524	1.1533	2.5008	0.98285	-0.0246	0.0173	0.0444	0.030225

Device Test: 19.34 VOLTAGE|VREF//14/14/0/0/5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

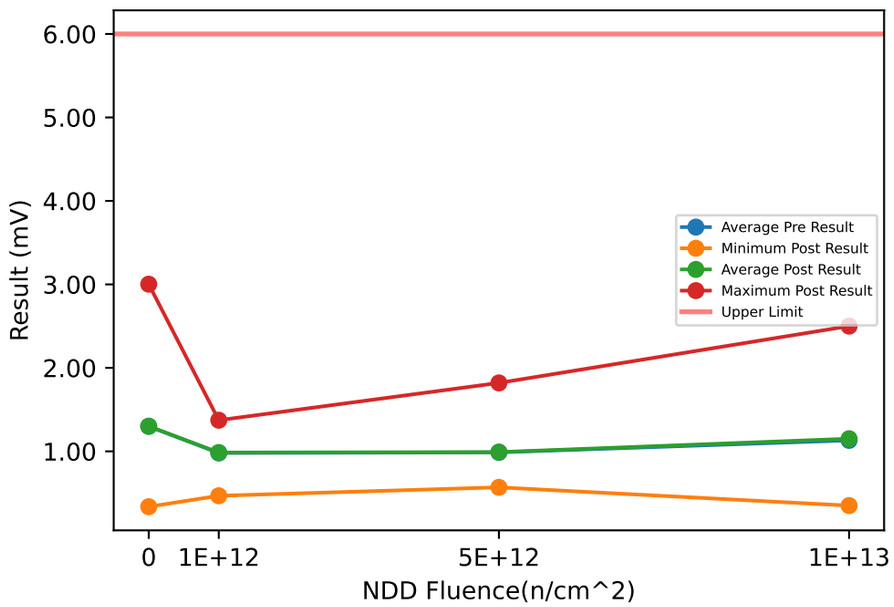
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60025	0.6002	-5e-05
466	1e+12	NDD	0.60022	0.59992	-0.0003
762	0	CORRELATION	0.59975	0.59973	-2e-05
769	1e+12	NDD	0.59989	0.59963	-0.00026
887	1e+12	NDD	0.60043	0.60011	-0.00032
891	0	CORRELATION	0.59983	0.59984	1e-05
927	1e+12	NDD	0.60036	0.6001	-0.00026
967	5e+12	NDD	0.60021	0.59894	-0.00127
1204	1e+13	NDD	0.60017	0.59776	-0.00241
1284	1e+13	NDD	0.5998	0.5975	-0.0023
1292	5e+12	NDD	0.60046	0.59928	-0.00118
1364	1e+13	NDD	0.60042	0.59783	-0.00259
1383	5e+12	NDD	0.60043	0.59936	-0.00107
1388	5e+12	NDD	0.60031	0.59913	-0.00118
1427	1e+13	NDD	0.60029	0.59802	-0.00227
1666	0	CORRELATION	0.60039	0.60036	-3e-05

Test Statistics (V)

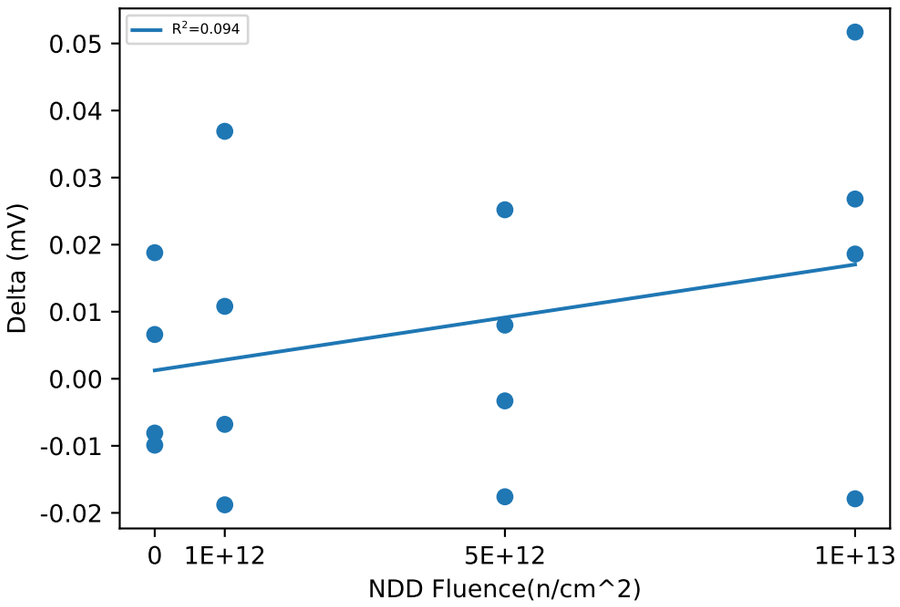
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59975	0.60006	0.60039	0.000313	0.59973	0.60003	0.60036	0.00029658	-5e-05	-2.25e-05	1e-05	2.5e-05
1e+12	0.59989	0.60023	0.60043	0.00023979	0.59963	0.59994	0.60011	0.00022435	-0.00032	-0.000285	-0.00026	3e-05
5e+12	0.60021	0.60035	0.60046	0.000115	0.59894	0.59918	0.59936	0.00018482	-0.00127	-0.001175	-0.00107	8.1854e-05
1e+13	0.5998	0.60017	0.60042	0.00026696	0.5975	0.59778	0.59802	0.00021515	-0.00259	-0.0023925	-0.00227	0.00014477

Device Test: 19.36 VOLTAGE|OFFSET//14/14/0/0/5/100kHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

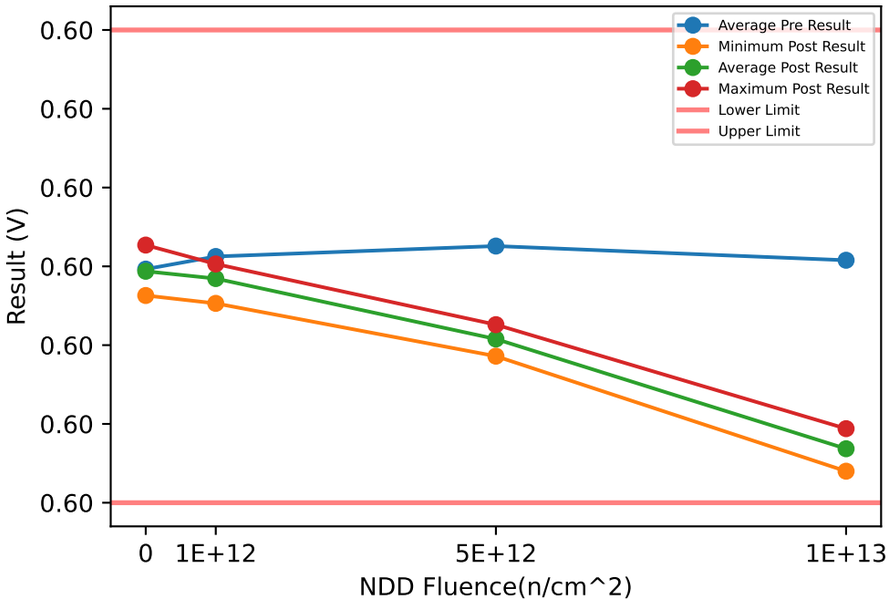
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.0124	3.0025	-0.0099
466	1e+12	NDD	1.376	1.3572	-0.0188
762	0	CORRELATION	0.3447	0.3366	-0.0081
769	1e+12	NDD	0.7347	0.7455	0.0108
887	1e+12	NDD	1.3797	1.3729	-0.0068
891	0	CORRELATION	1.1637	1.1825	0.0188
927	1e+12	NDD	0.4309	0.4678	0.0369
967	5e+12	NDD	0.5721	0.5688	-0.0033
1204	1e+13	NDD	0.3679	0.35	-0.0179
1284	1e+13	NDD	0.4513	0.503	0.0517
1292	5e+12	NDD	0.9166	0.9246	0.008
1364	1e+13	NDD	1.2249	1.2517	0.0268
1383	5e+12	NDD	1.7944	1.8196	0.0252
1388	5e+12	NDD	0.6684	0.6508	-0.0176
1427	1e+13	NDD	2.4816	2.5002	0.0186
1666	0	CORRELATION	0.6769	0.6835	0.0066

Test Statistics (mV)

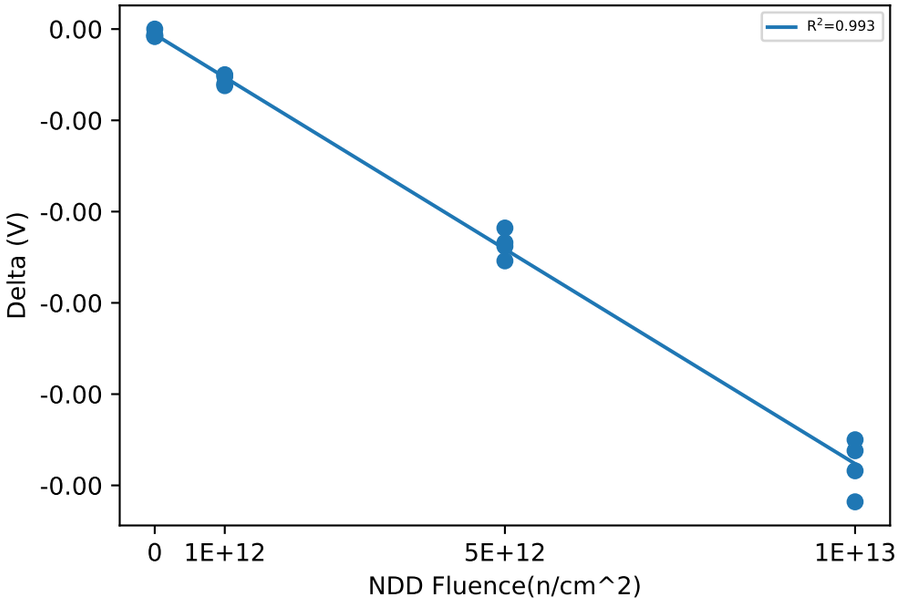
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3447	1.2994	3.0124	1.1905	0.3366	1.3013	3.0025	1.1861	-0.0099	0.00185	0.0188	0.013502
1e+12	0.4309	0.98032	1.3797	0.47549	0.4678	0.98585	1.3729	0.45235	-0.0188	0.005525	0.0369	0.024192
5e+12	0.5721	0.98788	1.7944	0.55692	0.5688	0.99095	1.8196	0.573	-0.0176	0.003075	0.0252	0.018091
1e+13	0.3679	1.1314	2.4816	0.97933	0.35	1.1512	2.5002	0.98183	-0.0179	0.0198	0.0517	0.028806

Device Test: 19.37 VOLTAGE|VREF//4.5/4.5/0/0/4.5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



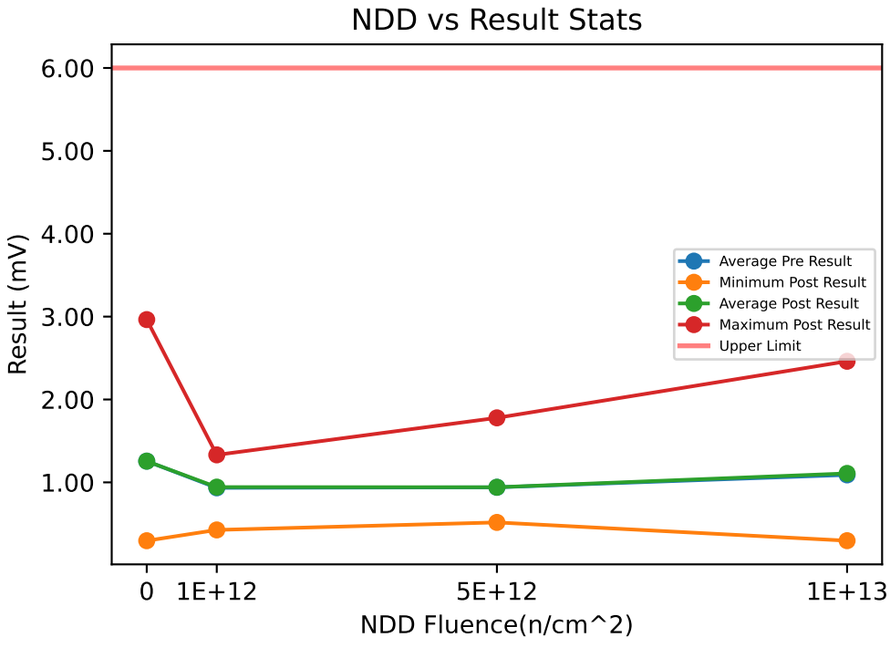
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

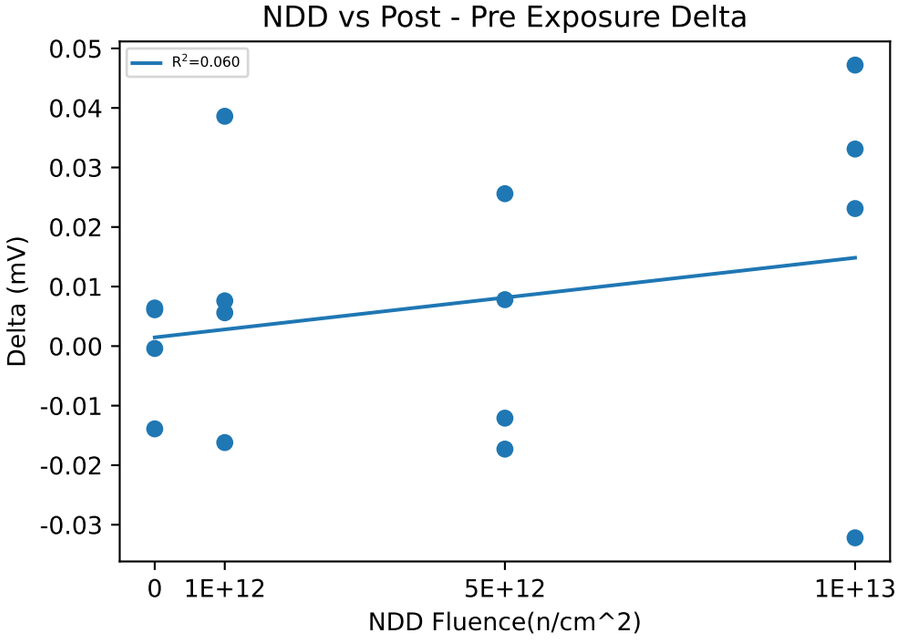
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60014	0.6001	-4e-05
466	1e+12	NDD	0.60011	0.59981	-0.0003
762	0	CORRELATION	0.59966	0.59963	-3e-05
769	1e+12	NDD	0.59978	0.59953	-0.00025
887	1e+12	NDD	0.60034	0.60003	-0.00031
891	0	CORRELATION	0.59975	0.59975	0
927	1e+12	NDD	0.60027	0.60001	-0.00026
967	5e+12	NDD	0.60013	0.59886	-0.00127
1204	1e+13	NDD	0.60008	0.59766	-0.00242
1284	1e+13	NDD	0.59971	0.5974	-0.00231
1292	5e+12	NDD	0.60034	0.59917	-0.00117
1364	1e+13	NDD	0.60033	0.59774	-0.00259
1383	5e+12	NDD	0.60035	0.59926	-0.00109
1388	5e+12	NDD	0.60021	0.59902	-0.00119
1427	1e+13	NDD	0.60019	0.59794	-0.00225
1666	0	CORRELATION	0.60031	0.60027	-4e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59966	0.59996	0.60031	0.00031032	0.59963	0.59994	0.60027	0.00029815	-4e-05	-2.75e-05	0	1.893e-05
1e+12	0.59978	0.60013	0.60034	0.00024933	0.59953	0.59984	0.60003	0.00023231	-0.00031	-0.00028	-0.00025	2.9439e-05
5e+12	0.60013	0.60026	0.60035	0.00010626	0.59886	0.59908	0.59926	0.00017557	-0.00127	-0.00118	-0.00109	7.3937e-05
1e+13	0.59971	0.60008	0.60033	0.0002655	0.5974	0.59769	0.59794	0.00022353	-0.00259	-0.0023925	-0.00225	0.0001493

Device Test: 19.39 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/500kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

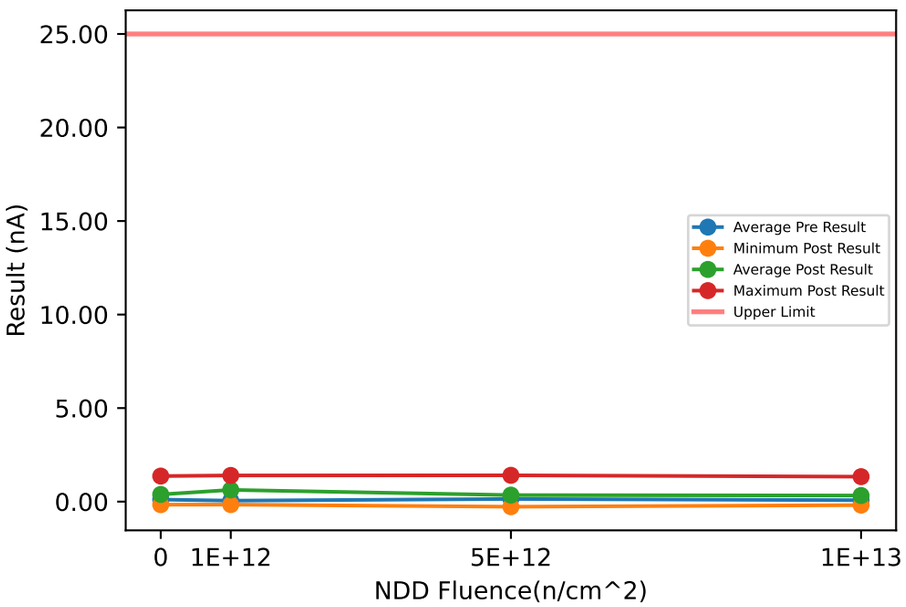
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.9578	2.9639	0.0061
466	1e+12	NDD	1.3276	1.3114	-0.0162
762	0	CORRELATION	0.2963	0.2959	-0.0004
769	1e+12	NDD	0.6967	0.7023	0.0056
887	1e+12	NDD	1.3242	1.3318	0.0076
891	0	CORRELATION	1.1285	1.1349	0.0064
927	1e+12	NDD	0.3875	0.4261	0.0386
967	5e+12	NDD	0.5288	0.5167	-0.0121
1204	1e+13	NDD	0.3286	0.2964	-0.0322
1284	1e+13	NDD	0.4099	0.4571	0.0472
1292	5e+12	NDD	0.8641	0.8719	0.0078
1364	1e+13	NDD	1.1839	1.217	0.0331
1383	5e+12	NDD	1.7529	1.7785	0.0256
1388	5e+12	NDD	0.615	0.5977	-0.0173
1427	1e+13	NDD	2.438	2.4611	0.0231
1666	0	CORRELATION	0.6423	0.6284	-0.0139

Test Statistics (mV)

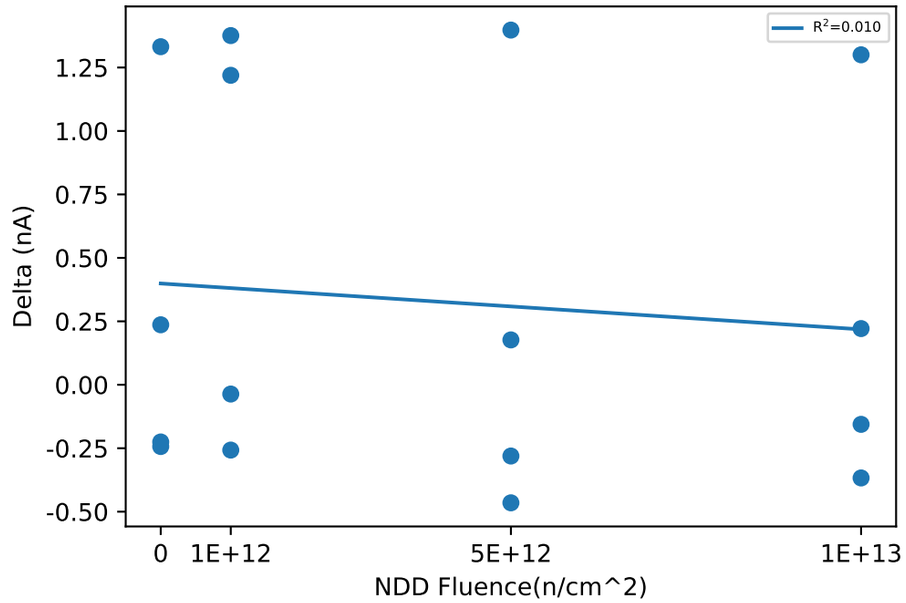
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2963	1.2562	2.9578	1.1846	0.2959	1.2558	2.9639	1.1899	-0.0139	-0.00045	0.0064	0.0094996
1e+12	0.3875	0.934	1.3276	0.46981	0.4261	0.9429	1.3318	0.45167	-0.0162	0.0089	0.0386	0.022544
5e+12	0.5288	0.9402	1.7529	0.56014	0.5167	0.9412	1.7785	0.57852	-0.0173	0.001	0.0256	0.019646
1e+13	0.3286	1.0901	2.438	0.97778	0.2964	1.1079	2.4611	0.98744	-0.0322	0.0178	0.0472	0.034768

Device Test: 19.4 CURRENT|EA//4.5/4.5/0/0/4.5/500kHz//@EA_IB

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 25.0 (nA))

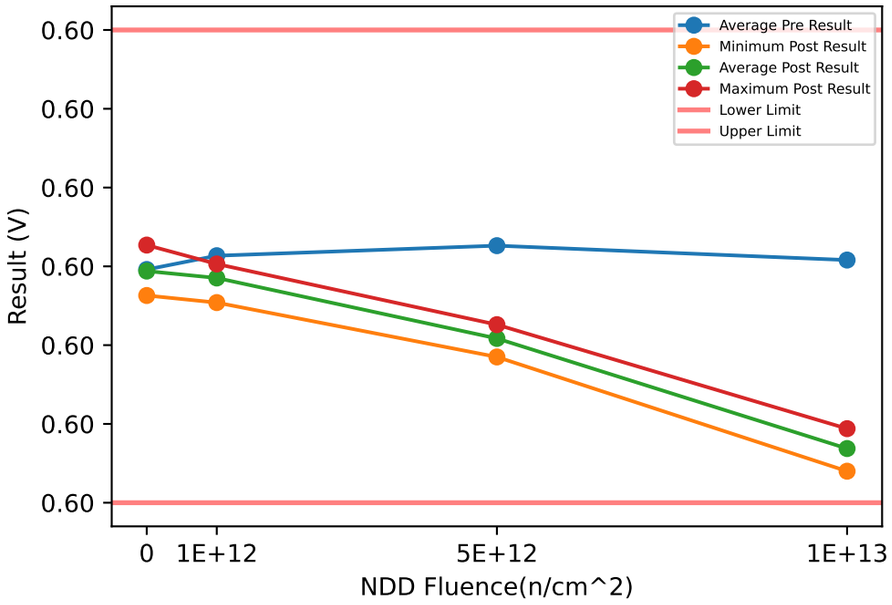
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.1646	0.401	0.2364
466	1e+12	NDD	0.1802	1.3995	1.2193
762	0	CORRELATION	0.062	-0.1634	-0.2254
769	1e+12	NDD	-0.0636	1.3122	1.3758
887	1e+12	NDD	-0.0067	-0.0432	-0.0365
891	0	CORRELATION	0.1751	-0.0682	-0.2433
927	1e+12	NDD	0.0971	-0.1602	-0.2573
967	5e+12	NDD	0.0082	1.4057	1.3975
1204	1e+13	NDD	0.0971	-0.0588	-0.1559
1284	1e+13	NDD	0.1802	-0.1869	-0.3671
1292	5e+12	NDD	0.2188	-0.0619	-0.2807
1364	1e+13	NDD	-0.0043	0.2171	0.2214
1383	5e+12	NDD	0.1463	0.3231	0.1768
1388	5e+12	NDD	0.1926	-0.2725	-0.4651
1427	1e+13	NDD	0.0339	1.334	1.3001
1666	0	CORRELATION	0.0332	1.3652	1.332

Test Statistics (nA)

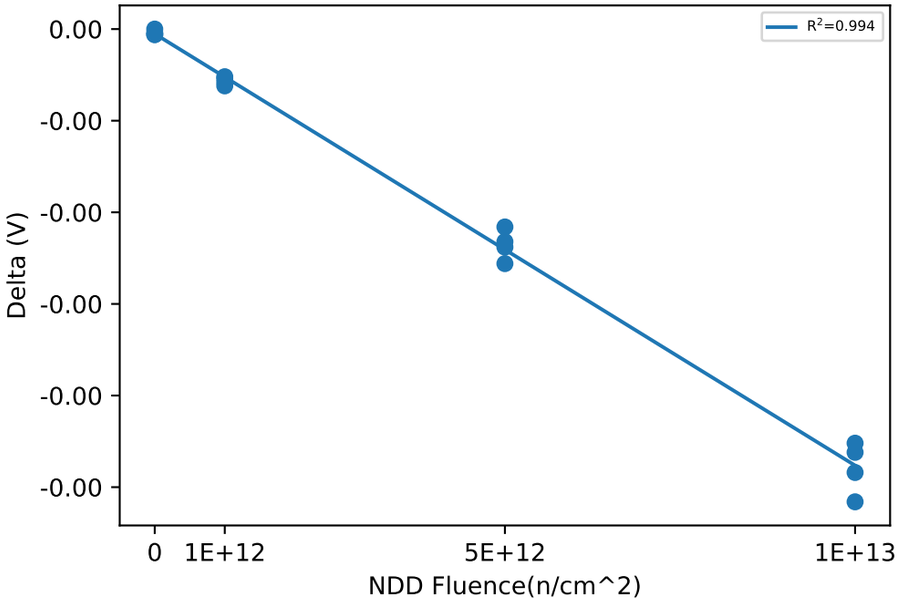
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0332	0.10873	0.1751	0.071682	-0.1634	0.38365	1.3652	0.69933	-0.2433	0.27493	1.332	0.73887
1e+12	-0.0636	0.05175	0.1802	0.10844	-0.1602	0.62708	1.3995	0.84362	-0.2573	0.57533	1.3758	0.84124
5e+12	0.0082	0.14148	0.2188	0.09377	-0.2725	0.3486	1.4057	0.74663	-0.4651	0.20712	1.3975	0.83821
1e+13	-0.0043	0.076725	0.1802	0.080666	-0.1869	0.32635	1.334	0.69259	-0.3671	0.24962	1.3001	0.74142

Device Test: 19.40 VOLTAGE|VREF//5/5/0/0/5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



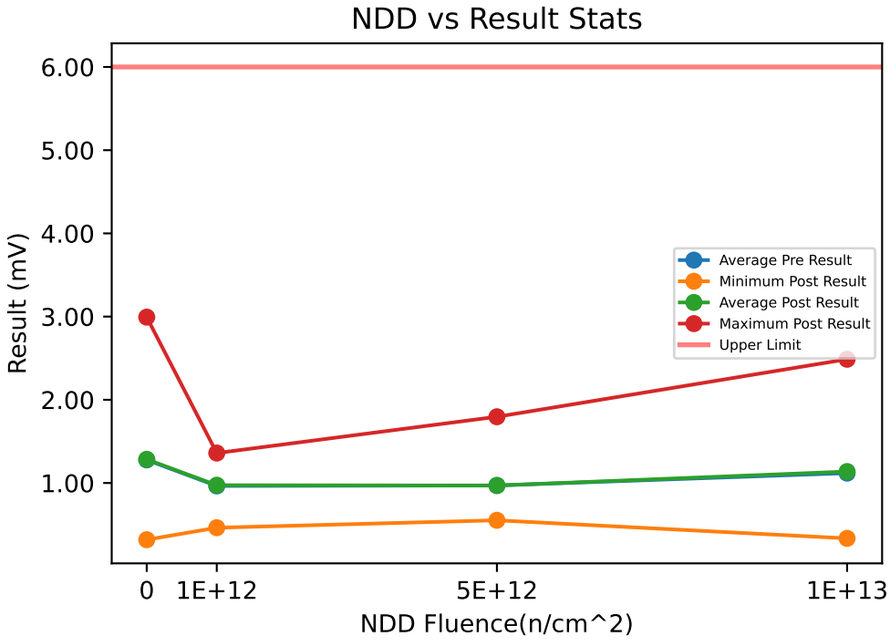
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

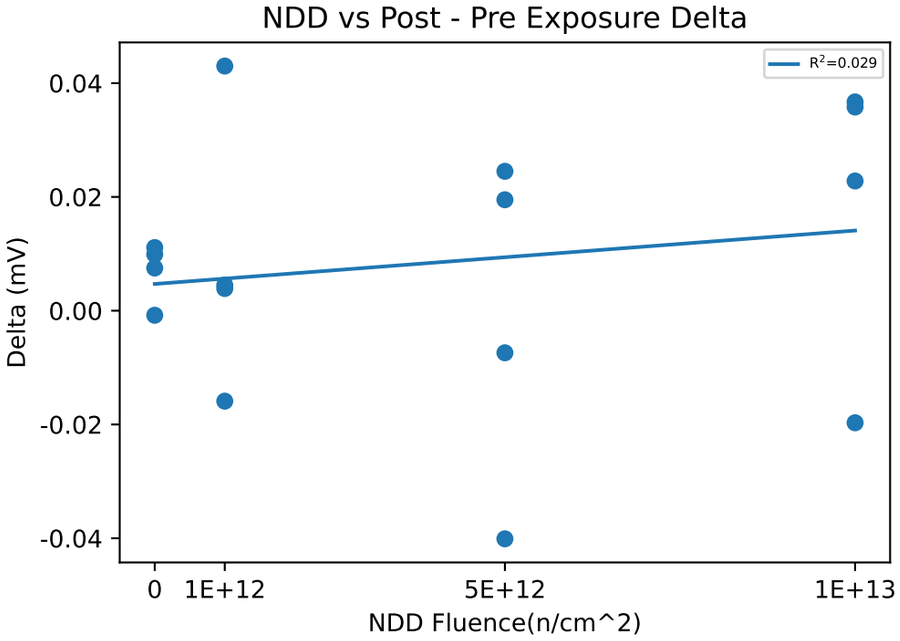
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60015	0.60012	-3e-05
466	1e+12	NDD	0.60012	0.59983	-0.00029
762	0	CORRELATION	0.59965	0.59963	-2e-05
769	1e+12	NDD	0.5998	0.59954	-0.00026
887	1e+12	NDD	0.60034	0.60003	-0.00031
891	0	CORRELATION	0.59974	0.59974	0
927	1e+12	NDD	0.60028	0.60001	-0.00027
967	5e+12	NDD	0.60013	0.59885	-0.00128
1204	1e+13	NDD	0.60008	0.59766	-0.00242
1284	1e+13	NDD	0.59971	0.5974	-0.00231
1292	5e+12	NDD	0.60035	0.59919	-0.00116
1364	1e+13	NDD	0.60033	0.59775	-0.00258
1383	5e+12	NDD	0.60034	0.59926	-0.00108
1388	5e+12	NDD	0.60023	0.59904	-0.00119
1427	1e+13	NDD	0.6002	0.59794	-0.00226
1666	0	CORRELATION	0.6003	0.60027	-3e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59965	0.59996	0.6003	0.00031422	0.59963	0.59994	0.60027	0.00030408	-3e-05	-2e-05	0	1.4142e-05
1e+12	0.5998	0.60013	0.60034	0.00024187	0.59954	0.59985	0.60003	0.00022692	-0.00031	-0.0002825	-0.00026	2.2174e-05
5e+12	0.60013	0.60026	0.60035	0.00010372	0.59885	0.59908	0.59926	0.00018157	-0.00128	-0.0011775	-0.00108	8.2614e-05
1e+13	0.59971	0.60008	0.60033	0.00026696	0.5974	0.59769	0.59794	0.00022441	-0.00258	-0.0023925	-0.00226	0.00014175

Device Test: 19.42 VOLTAGE|OFFSET//5/5/0/0/5/500kHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

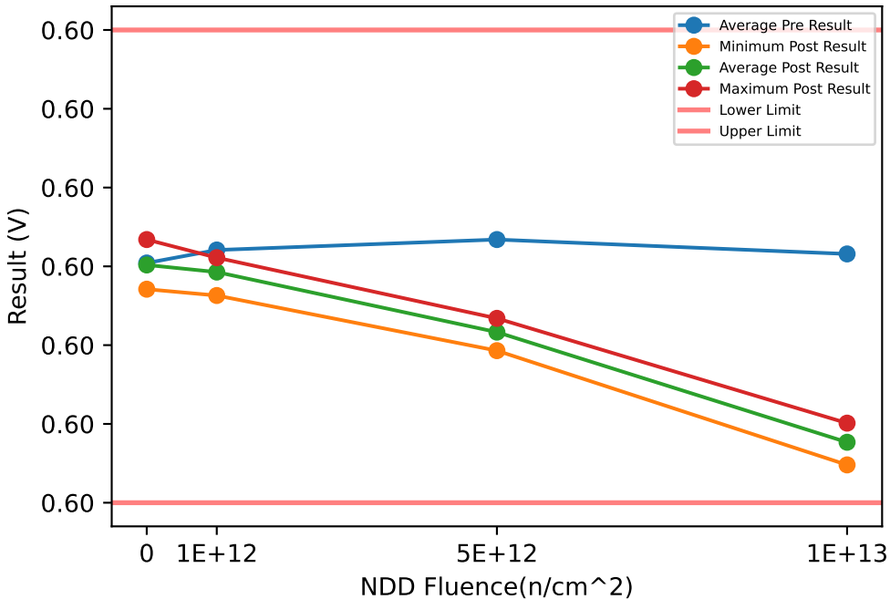
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.9859	2.9934	0.0075
466	1e+12	NDD	1.3632	1.3473	-0.0159
762	0	CORRELATION	0.3189	0.3181	-0.0008
769	1e+12	NDD	0.7203	0.7242	0.0039
887	1e+12	NDD	1.3552	1.3597	0.0045
891	0	CORRELATION	1.148	1.1579	0.0099
927	1e+12	NDD	0.4193	0.4623	0.043
967	5e+12	NDD	0.5589	0.5515	-0.0074
1204	1e+13	NDD	0.3542	0.3345	-0.0197
1284	1e+13	NDD	0.4462	0.482	0.0358
1292	5e+12	NDD	0.8893	0.9088	0.0195
1364	1e+13	NDD	1.2093	1.246	0.0367
1383	5e+12	NDD	1.7714	1.7959	0.0245
1388	5e+12	NDD	0.6619	0.6218	-0.0401
1427	1e+13	NDD	2.4643	2.4871	0.0228
1666	0	CORRELATION	0.6576	0.6687	0.0111

Test Statistics (mV)

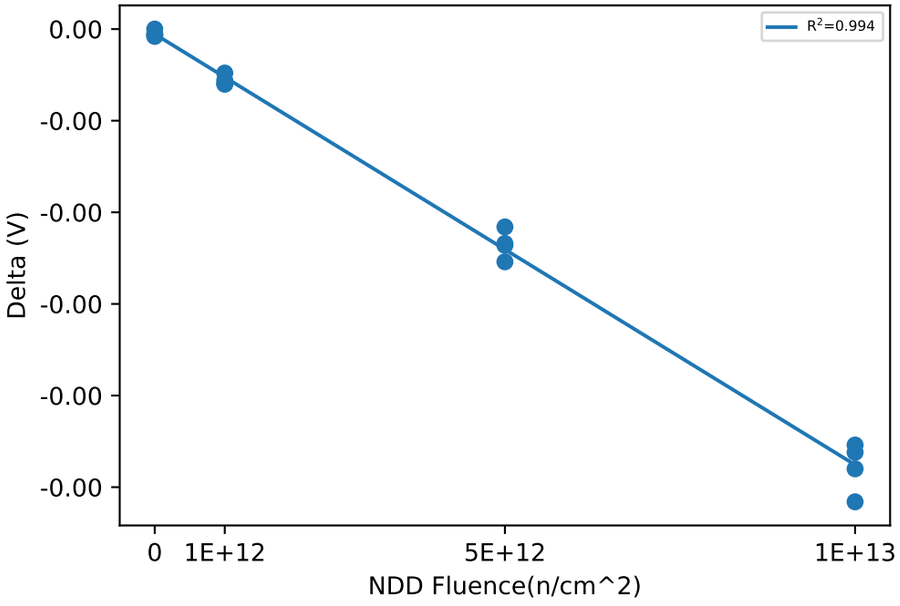
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3189	1.2776	2.9859	1.1886	0.3181	1.2845	2.9934	1.1902	-0.0008	0.006925	0.0111	0.0053631
1e+12	0.4193	0.9645	1.3632	0.47205	0.4623	0.97337	1.3597	0.45179	-0.0159	0.008875	0.043	0.024646
5e+12	0.5589	0.97037	1.7714	0.55157	0.5515	0.9695	1.7959	0.5722	-0.0401	-0.000875	0.0245	0.029666
1e+13	0.3542	1.1185	2.4643	0.97563	0.3345	1.1374	2.4871	0.98449	-0.0197	0.0189	0.0367	0.026505

Device Test: 19.43 VOLTAGE|VREF//12/12/0/0/5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

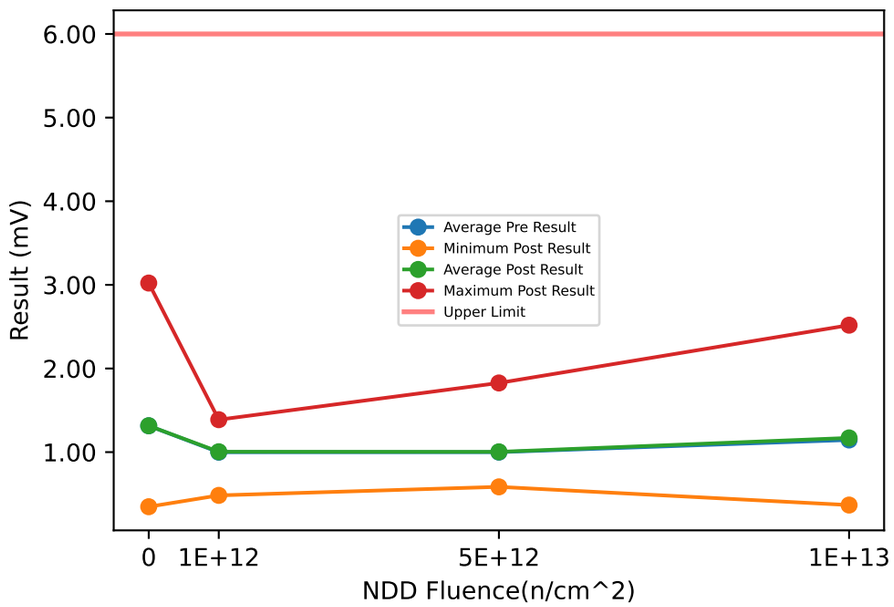
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60023	0.60019	-4e-05
466	1e+12	NDD	0.6002	0.5999	-0.0003
762	0	CORRELATION	0.59974	0.59971	-3e-05
769	1e+12	NDD	0.59987	0.59963	-0.00024
887	1e+12	NDD	0.60041	0.60011	-0.0003
891	0	CORRELATION	0.59983	0.59983	0
927	1e+12	NDD	0.60035	0.60007	-0.00028
967	5e+12	NDD	0.6002	0.59893	-0.00127
1204	1e+13	NDD	0.60016	0.59776	-0.0024
1284	1e+13	NDD	0.59979	0.59748	-0.00231
1292	5e+12	NDD	0.60044	0.59927	-0.00117
1364	1e+13	NDD	0.6004	0.59782	-0.00258
1383	5e+12	NDD	0.60042	0.59934	-0.00108
1388	5e+12	NDD	0.6003	0.59912	-0.00118
1427	1e+13	NDD	0.60028	0.59801	-0.00227
1666	0	CORRELATION	0.60037	0.60034	-3e-05

Test Statistics (V)

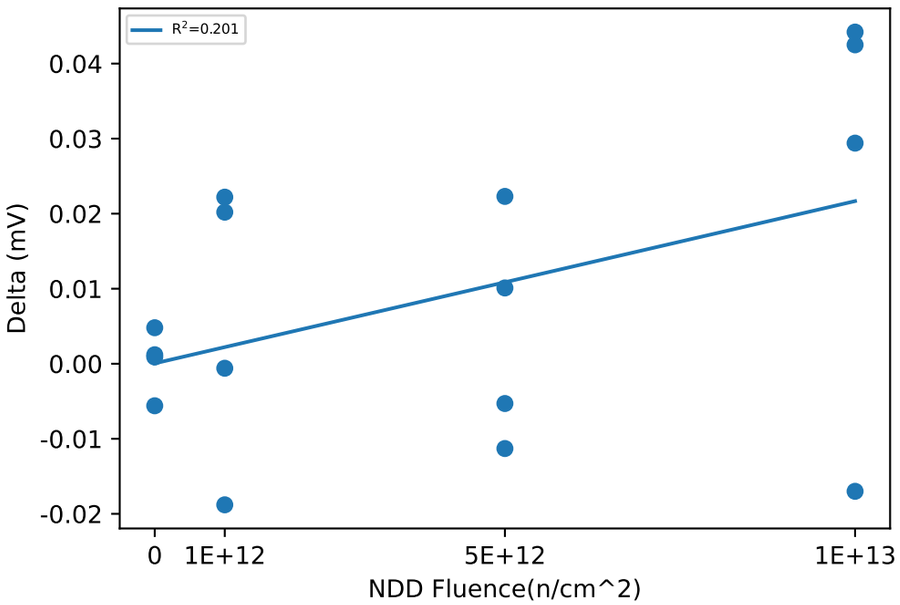
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59974	0.60004	0.60037	0.000305	0.59971	0.60002	0.60034	0.00029635	-4e-05	-2.5e-05	0	1.7321e-05
1e+12	0.59987	0.60021	0.60041	0.00024171	0.59963	0.59993	0.60011	0.00021823	-0.0003	-0.00028	-0.00024	2.8284e-05
5e+12	0.6002	0.60034	0.60044	0.00011195	0.59893	0.59916	0.59934	0.00018157	-0.00127	-0.001175	-0.00108	7.7675e-05
1e+13	0.59979	0.60016	0.6004	0.00026387	0.59748	0.59777	0.59801	0.0002193	-0.00258	-0.00239	-0.00227	0.00013784

Device Test: 19.45 VOLTAGE|OFFSET//12/12/0/0/5/500kHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

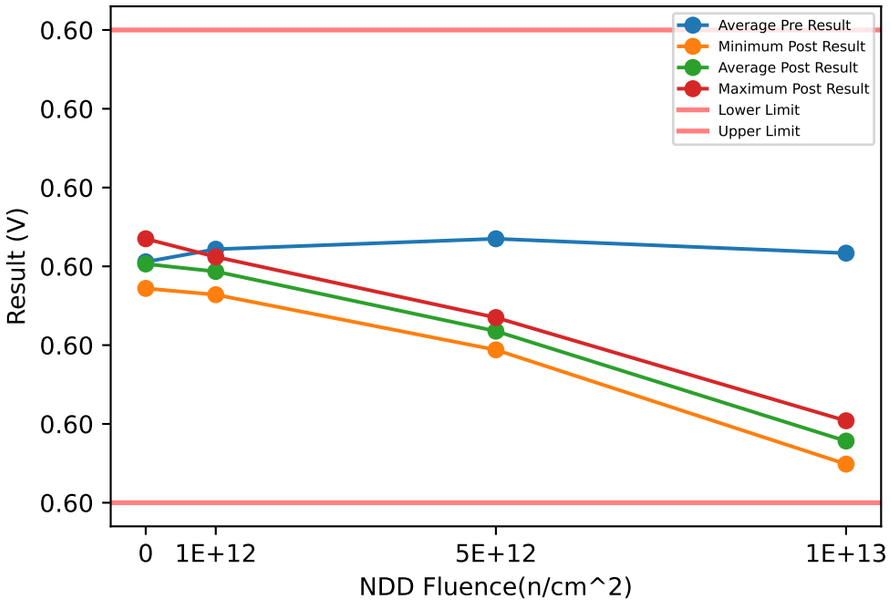
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.0208	3.0217	0.0009
466	1e+12	NDD	1.3922	1.3734	-0.0188
762	0	CORRELATION	0.3527	0.3471	-0.0056
769	1e+12	NDD	0.7519	0.7741	0.0222
887	1e+12	NDD	1.3884	1.3878	-0.0006
891	0	CORRELATION	1.1906	1.1954	0.0048
927	1e+12	NDD	0.4625	0.4827	0.0202
967	5e+12	NDD	0.5899	0.5846	-0.0053
1204	1e+13	NDD	0.3841	0.3671	-0.017
1284	1e+13	NDD	0.4716	0.5158	0.0442
1292	5e+12	NDD	0.9238	0.9339	0.0101
1364	1e+13	NDD	1.2361	1.2786	0.0425
1383	5e+12	NDD	1.8045	1.8268	0.0223
1388	5e+12	NDD	0.6797	0.6684	-0.0113
1427	1e+13	NDD	2.4886	2.518	0.0294
1666	0	CORRELATION	0.6961	0.6973	0.0012

Test Statistics (mV)

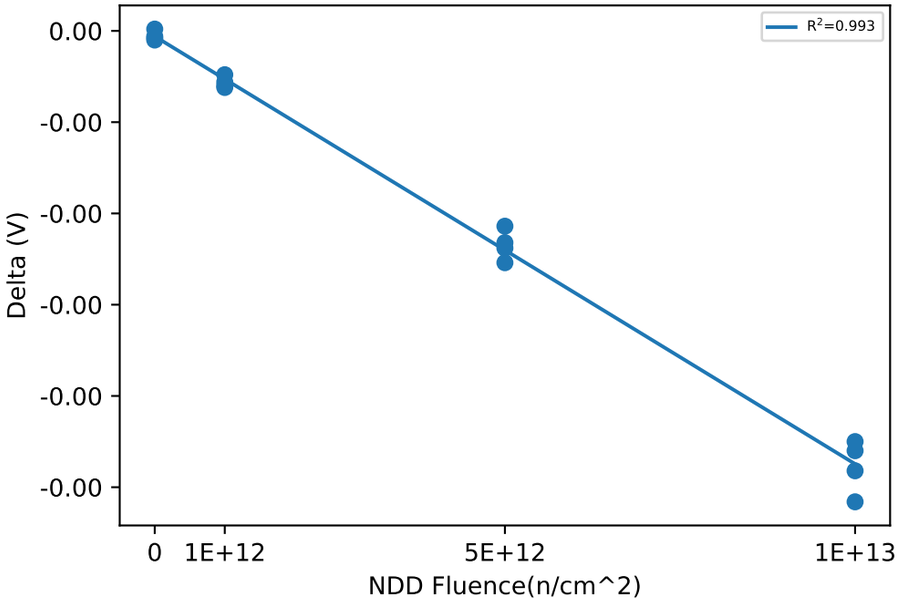
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3527	1.3151	3.0208	1.188	0.3471	1.3154	3.0217	1.1896	-0.0056	0.000325	0.0048	0.0043293
1e+12	0.4625	0.99875	1.3922	0.46731	0.4827	1.0045	1.3878	0.45032	-0.0188	0.00575	0.0222	0.019343
5e+12	0.5899	0.99948	1.8045	0.55492	0.5846	1.0034	1.8268	0.56875	-0.0113	0.00395	0.0223	0.015195
1e+13	0.3841	1.1451	2.4886	0.97399	0.3671	1.1699	2.518	0.98345	-0.017	0.024775	0.0442	0.028624

Device Test: 19.46 VOLTAGE|VREF//14/14/0/0/5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

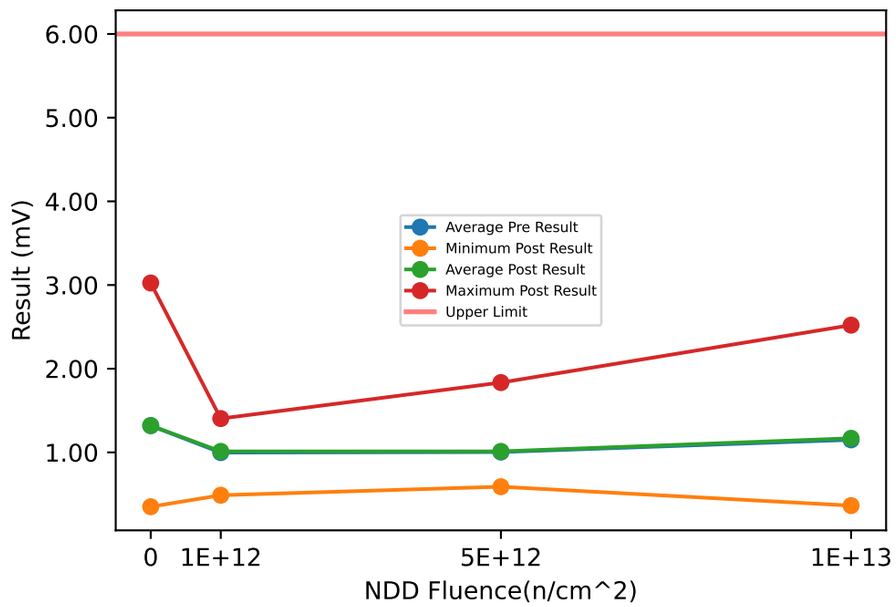
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60025	0.6002	-5e-05
466	1e+12	NDD	0.60021	0.5999	-0.00031
762	0	CORRELATION	0.59975	0.59972	-3e-05
769	1e+12	NDD	0.59988	0.59964	-0.00024
887	1e+12	NDD	0.60042	0.60012	-0.0003
891	0	CORRELATION	0.59984	0.59985	1e-05
927	1e+12	NDD	0.60036	0.60008	-0.00028
967	5e+12	NDD	0.60021	0.59894	-0.00127
1204	1e+13	NDD	0.60018	0.59777	-0.00241
1284	1e+13	NDD	0.59979	0.59749	-0.0023
1292	5e+12	NDD	0.60045	0.59929	-0.00116
1364	1e+13	NDD	0.60041	0.59783	-0.00258
1383	5e+12	NDD	0.60042	0.59935	-0.00107
1388	5e+12	NDD	0.60032	0.59913	-0.00119
1427	1e+13	NDD	0.60029	0.59804	-0.00225
1666	0	CORRELATION	0.60039	0.60035	-4e-05

Test Statistics (V)

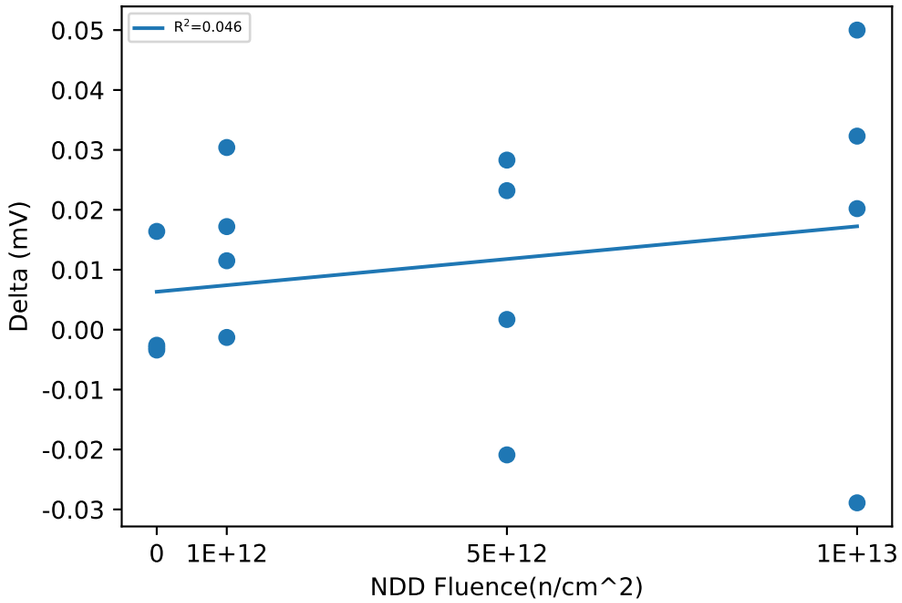
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59975	0.60006	0.60039	0.00031063	0.59972	0.60003	0.60035	0.00029428	-5e-05	-2.75e-05	1e-05	2.63e-05
1e+12	0.59988	0.60022	0.60042	0.00024171	0.59964	0.59993	0.60012	0.00021871	-0.00031	-0.0002825	-0.00024	3.0957e-05
5e+12	0.60021	0.60035	0.60045	0.00010863	0.59894	0.59918	0.59935	0.00018355	-0.00127	-0.0011725	-0.00107	8.2614e-05
1e+13	0.59979	0.60017	0.60041	0.00026862	0.59749	0.59778	0.59804	0.00022677	-0.00258	-0.002385	-0.00225	0.00014617

Device Test: 19.48 VOLTAGE|OFFSET//14/14/0/0/5/500kHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

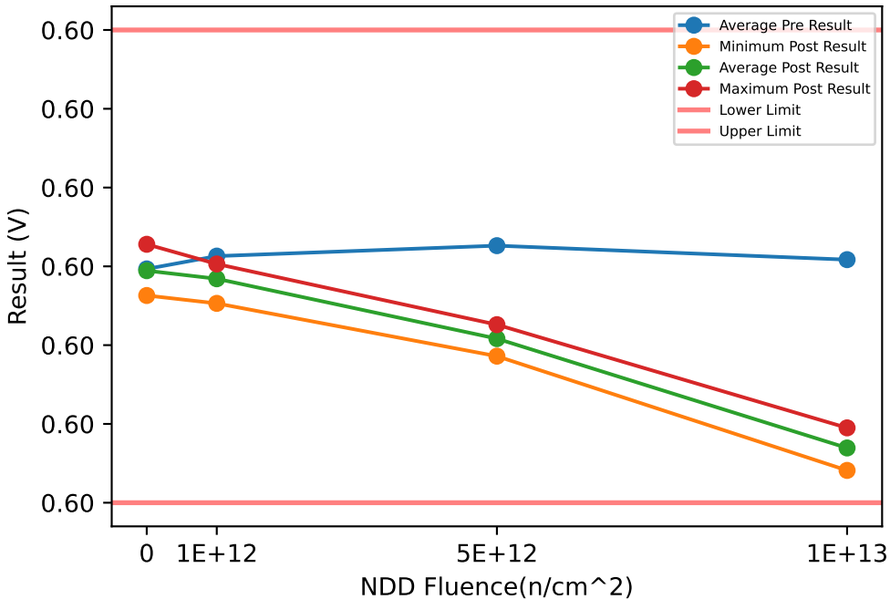
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.0269	3.0243	-0.0026
466	1e+12	NDD	1.3881	1.3868	-0.0013
762	0	CORRELATION	0.3541	0.3507	-0.0034
769	1e+12	NDD	0.7514	0.7686	0.0172
887	1e+12	NDD	1.3926	1.4041	0.0115
891	0	CORRELATION	1.192	1.2084	0.0164
927	1e+12	NDD	0.4577	0.4881	0.0304
967	5e+12	NDD	0.588	0.5897	0.0017
1204	1e+13	NDD	0.3932	0.3643	-0.0289
1284	1e+13	NDD	0.4642	0.5142	0.05
1292	5e+12	NDD	0.9317	0.9549	0.0232
1364	1e+13	NDD	1.2422	1.2745	0.0323
1383	5e+12	NDD	1.8058	1.8341	0.0283
1388	5e+12	NDD	0.6899	0.669	-0.0209
1427	1e+13	NDD	2.5004	2.5206	0.0202
1666	0	CORRELATION	0.7042	0.7012	-0.003

Test Statistics (mV)

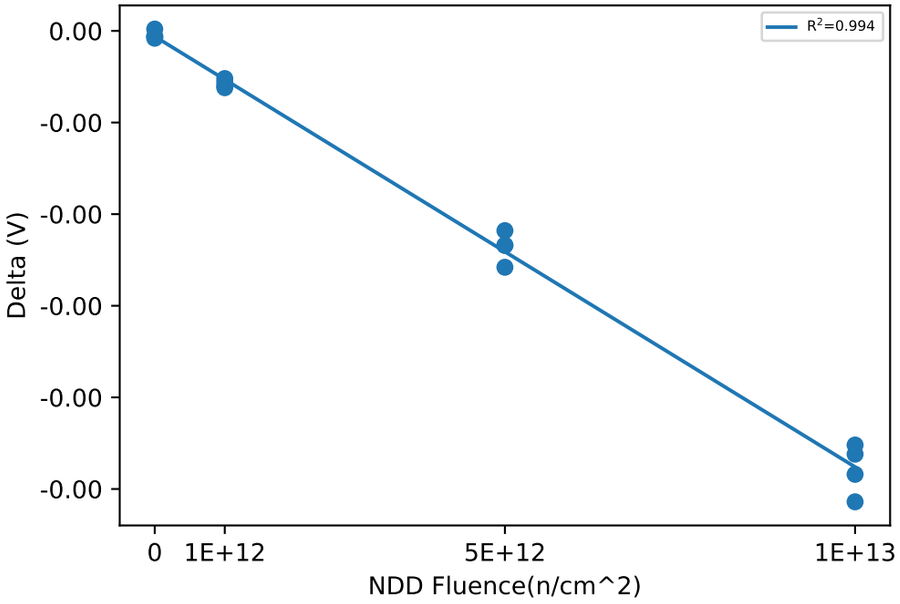
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3541	1.3193	3.0269	1.1891	0.3507	1.3212	3.0243	1.1888	-0.0034	0.00185	0.0164	0.0097055
1e+12	0.4577	0.99745	1.3926	0.46926	0.4881	1.0119	1.4041	0.4575	-0.0013	0.01445	0.0304	0.01315
5e+12	0.588	1.0038	1.8058	0.55372	0.5897	1.0119	1.8341	0.57012	-0.0209	0.008075	0.0283	0.022494
1e+13	0.3932	1.15	2.5004	0.97897	0.3643	1.1684	2.5206	0.98561	-0.0289	0.0184	0.05	0.033825

Device Test: 19.49 VOLTAGE|VREF//4.5/4.5/0/0/4.5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

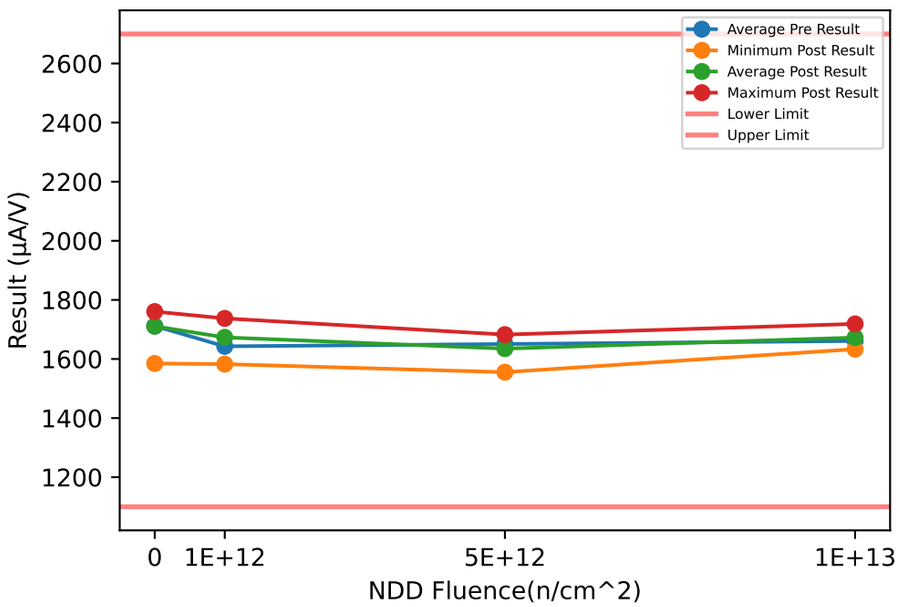
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60014	0.60011	-3e-05
466	1e+12	NDD	0.60012	0.59981	-0.00031
762	0	CORRELATION	0.59966	0.59963	-3e-05
769	1e+12	NDD	0.59979	0.59953	-0.00026
887	1e+12	NDD	0.60033	0.60003	-0.0003
891	0	CORRELATION	0.59975	0.59976	1e-05
927	1e+12	NDD	0.60028	0.6	-0.00028
967	5e+12	NDD	0.60015	0.59886	-0.00129
1204	1e+13	NDD	0.60009	0.59767	-0.00242
1284	1e+13	NDD	0.59972	0.59741	-0.00231
1292	5e+12	NDD	0.60035	0.59918	-0.00117
1364	1e+13	NDD	0.60032	0.59775	-0.00257
1383	5e+12	NDD	0.60035	0.59926	-0.00109
1388	5e+12	NDD	0.6002	0.59903	-0.00117
1427	1e+13	NDD	0.60021	0.59795	-0.00226
1666	0	CORRELATION	0.60032	0.60028	-4e-05

Test Statistics (V)

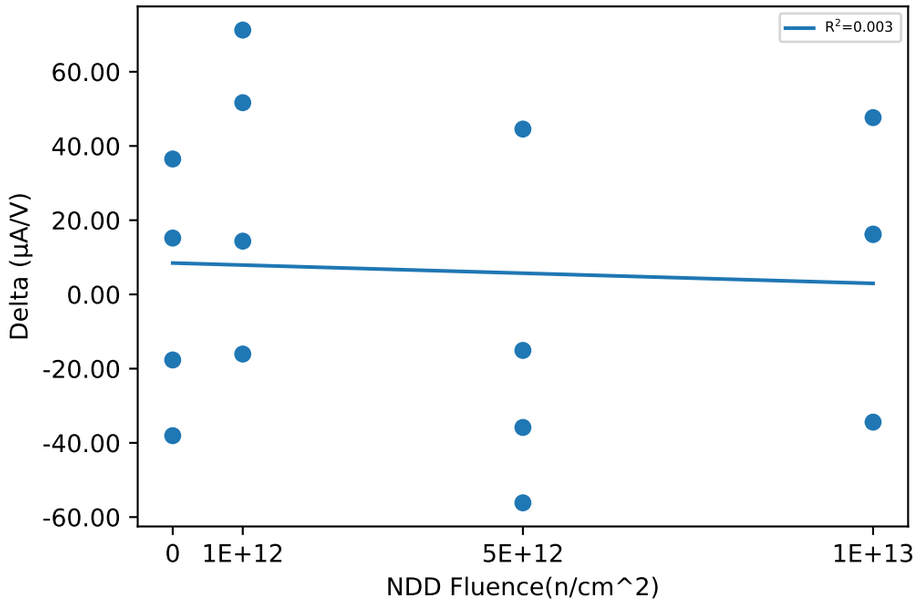
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59966	0.59997	0.60032	0.00031405	0.59963	0.59994	0.60028	0.00030161	-4e-05	-2.25e-05	1e-05	2.2174e-05
1e+12	0.59979	0.60013	0.60033	0.00024372	0.59953	0.59984	0.60003	0.00022998	-0.00031	-0.0002875	-0.00026	2.2174e-05
5e+12	0.60015	0.60026	0.60035	0.00010308	0.59886	0.59908	0.59926	0.00017633	-0.00129	-0.00118	-0.00109	8.2462e-05
1e+13	0.59972	0.60008	0.60032	0.00026083	0.59741	0.59769	0.59795	0.00022353	-0.00257	-0.00239	-0.00226	0.00013736

Device Test: 19.5 LEVEL|TRANSCONDUCTANCE//5/5/0/0/5/500kHz//@EA_GM

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



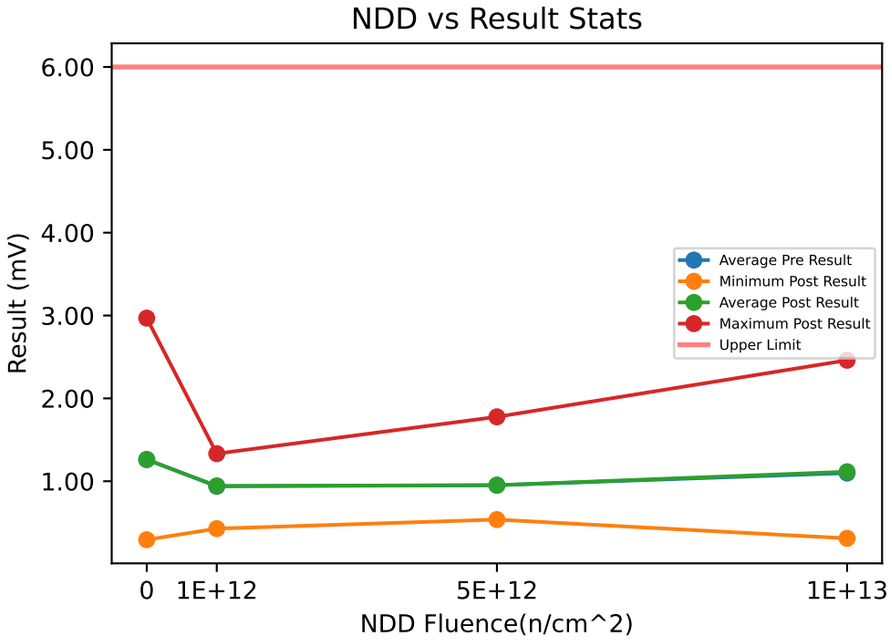
Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

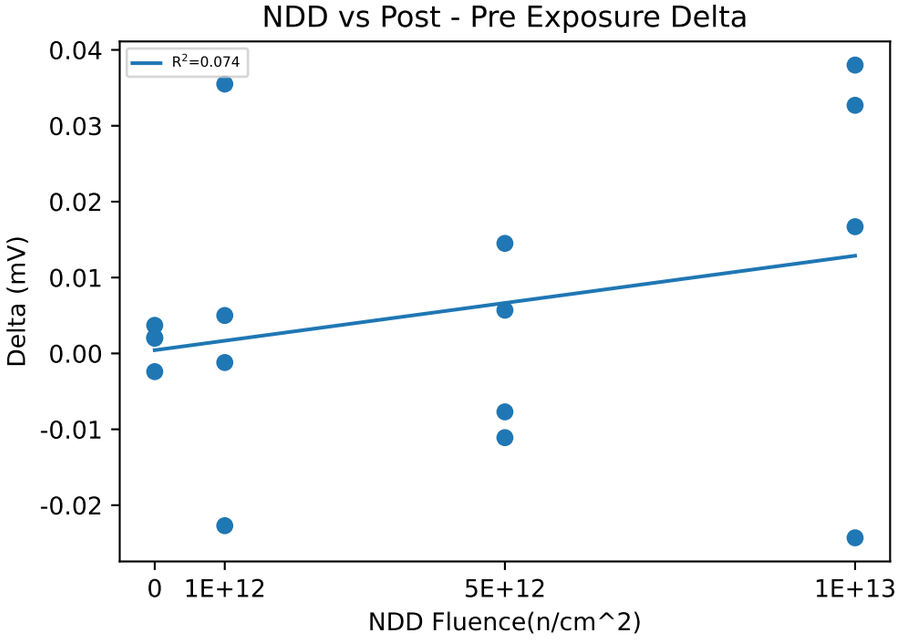
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1779.4	1741.3	-38.063
466	1e+12	NDD	1685.7	1737.4	51.664
762	0	CORRELATION	1778.1	1760.5	-17.66
769	1e+12	NDD	1568.2	1582.6	14.357
887	1e+12	NDD	1649.8	1721	71.233
891	0	CORRELATION	1569.5	1584.7	15.189
927	1e+12	NDD	1667.6	1651.6	-16.063
967	5e+12	NDD	1738.7	1682.5	-56.155
1204	1e+13	NDD	1617.1	1633.2	16.144
1284	1e+13	NDD	1585.6	1633.2	47.642
1292	5e+12	NDD	1703.1	1667.3	-35.847
1364	1e+13	NDD	1738.7	1704.3	-34.414
1383	5e+12	NDD	1649.8	1634.7	-15.087
1388	5e+12	NDD	1510.8	1555.4	44.553
1427	1e+13	NDD	1702.5	1718.7	16.255
1666	0	CORRELATION	1720	1756.5	36.492

Test Statistics (µA/V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1569.5	1711.8	1779.4	98.778	1584.7	1710.7	1760.5	84.417	-38.063	-1.0107	36.492	33.261
1e+12	1568.2	1642.9	1685.7	51.866	1582.6	1673.1	1737.4	70.921	-16.063	30.298	71.233	38.883
5e+12	1510.8	1650.6	1738.7	100.1	1555.4	1635	1682.5	56.697	-56.155	-15.634	44.553	43.487
1e+13	1585.6	1661	1738.7	71.573	1633.2	1672.4	1718.7	45.565	-34.414	11.406	47.642	33.954

Device Test: 19.51 VOLTAGE|OFFSET//4.5/4.5/0/0/4.5/1MHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

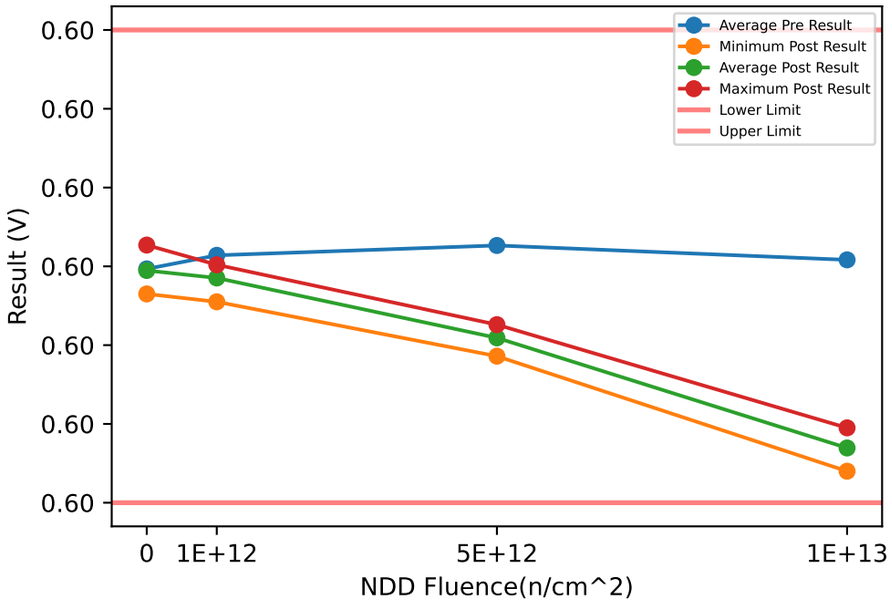
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.9667	2.9687	0.002
466	1e+12	NDD	1.3365	1.3138	-0.0227
762	0	CORRELATION	0.292	0.2941	0.0021
769	1e+12	NDD	0.6996	0.6984	-0.0012
887	1e+12	NDD	1.3278	1.3328	0.005
891	0	CORRELATION	1.1379	1.1416	0.0037
927	1e+12	NDD	0.3926	0.4281	0.0355
967	5e+12	NDD	0.5448	0.5371	-0.0077
1204	1e+13	NDD	0.3352	0.3109	-0.0243
1284	1e+13	NDD	0.4235	0.4615	0.038
1292	5e+12	NDD	0.8774	0.8831	0.0057
1364	1e+13	NDD	1.1922	1.2249	0.0327
1383	5e+12	NDD	1.7628	1.7773	0.0145
1388	5e+12	NDD	0.6224	0.6113	-0.0111
1427	1e+13	NDD	2.4435	2.4602	0.0167
1666	0	CORRELATION	0.6491	0.6467	-0.0024

Test Statistics (mV)

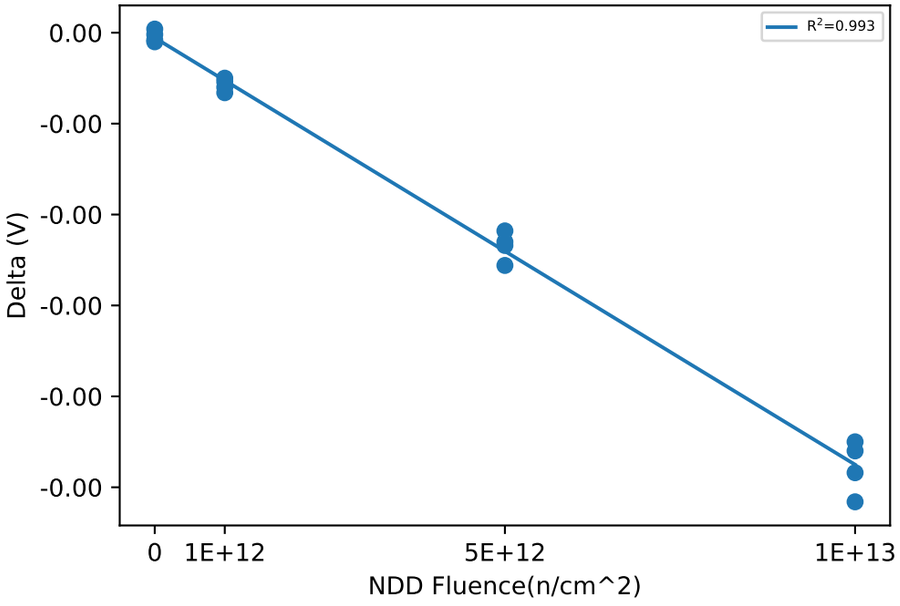
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.292	1.2614	2.9667	1.1885	0.2941	1.2628	2.9687	1.1892	-0.0024	0.00135	0.0037	0.0026185
1e+12	0.3926	0.93912	1.3365	0.47083	0.4281	0.94328	1.3328	0.45254	-0.0227	0.00415	0.0355	0.024035
5e+12	0.5448	0.95185	1.7628	0.55899	0.5371	0.9522	1.7773	0.56982	-0.0111	0.00035	0.0145	0.011899
1e+13	0.3352	1.0986	2.4435	0.97571	0.3109	1.1144	2.4602	0.98239	-0.0243	0.015775	0.038	0.028209

Device Test: 19.52 VOLTAGE|VREF//5/5/0/0/5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



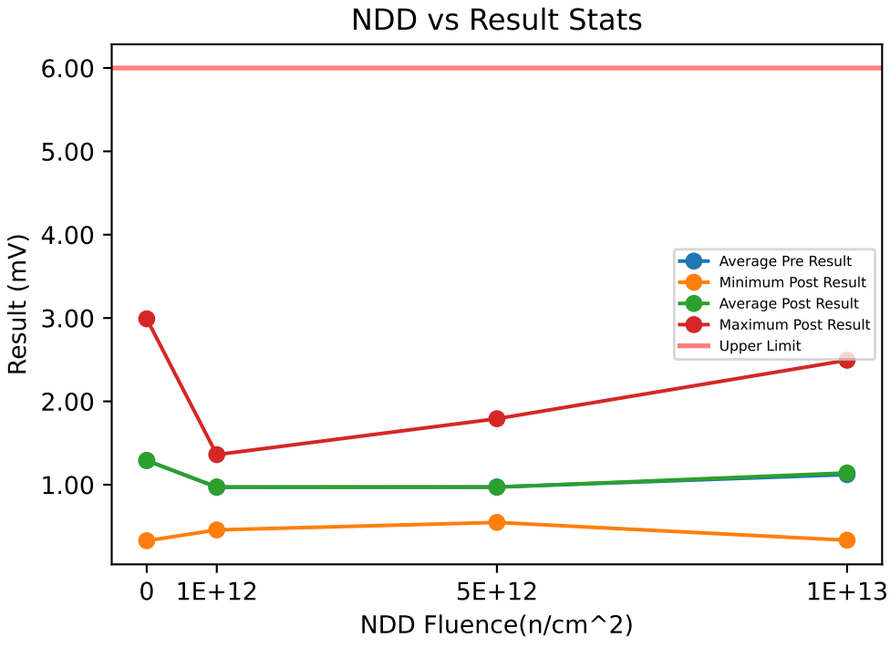
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

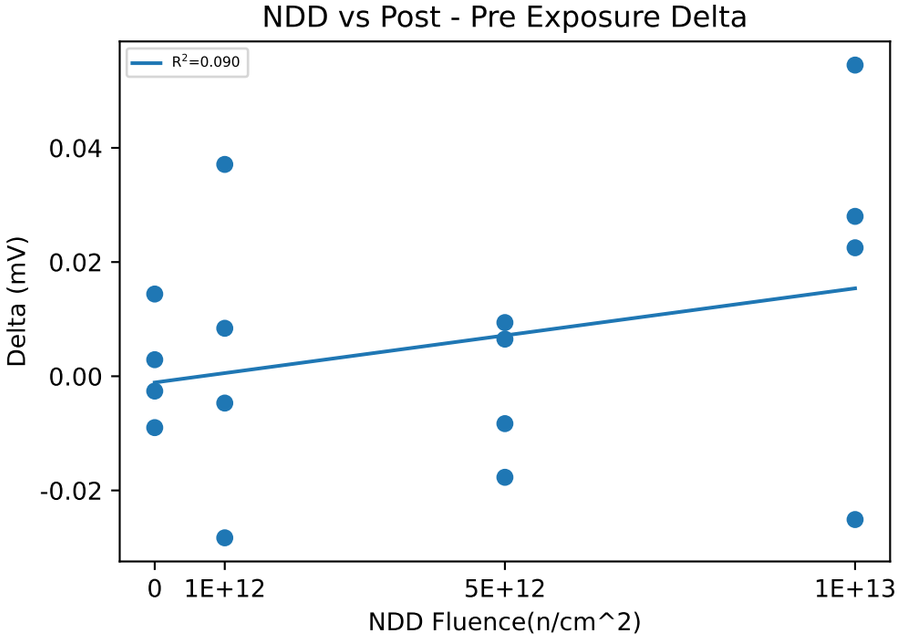
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60016	0.60011	-5e-05
466	1e+12	NDD	0.60013	0.59983	-0.0003
762	0	CORRELATION	0.59966	0.59965	-1e-05
769	1e+12	NDD	0.5998	0.59955	-0.00025
887	1e+12	NDD	0.60035	0.60002	-0.00033
891	0	CORRELATION	0.59974	0.59976	2e-05
927	1e+12	NDD	0.60028	0.60001	-0.00027
967	5e+12	NDD	0.60014	0.59886	-0.00128
1204	1e+13	NDD	0.60009	0.59767	-0.00242
1284	1e+13	NDD	0.5997	0.5974	-0.0023
1292	5e+12	NDD	0.60035	0.5992	-0.00115
1364	1e+13	NDD	0.60034	0.59776	-0.00258
1383	5e+12	NDD	0.60035	0.59926	-0.00109
1388	5e+12	NDD	0.60022	0.59905	-0.00117
1427	1e+13	NDD	0.6002	0.59795	-0.00225
1666	0	CORRELATION	0.60031	0.60027	-4e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59966	0.59997	0.60031	0.00031658	0.59965	0.59995	0.60027	0.00029102	-5e-05	-2e-05	2e-05	3.1623e-05
1e+12	0.5998	0.60014	0.60035	0.00024454	0.59955	0.59985	0.60002	0.00021975	-0.00033	-0.0002875	-0.00025	3.5e-05
5e+12	0.60014	0.60027	0.60035	0.00010344	0.59886	0.59909	0.59926	0.0001784	-0.00128	-0.0011725	-0.00109	7.932e-05
1e+13	0.5997	0.60008	0.60034	0.00027476	0.5974	0.59769	0.59795	0.00022869	-0.00258	-0.0023875	-0.00225	0.00014683

Device Test: 19.54 VOLTAGE|OFFSET//5/5/0/0/5/1MHz//@EA_OS





Test Results (Upper Limit = 6.0 (mV))

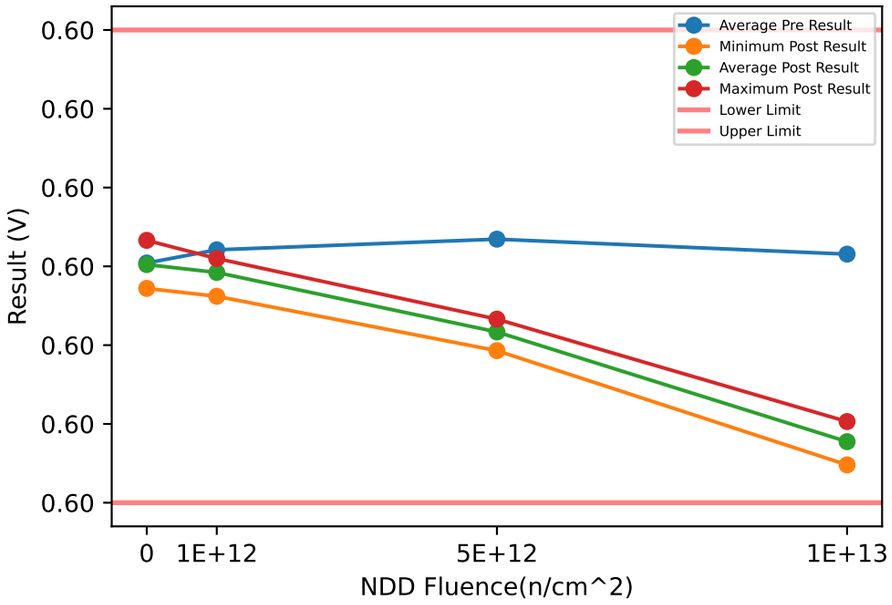
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.9994	2.9904	-0.009
466	1e+12	NDD	1.3687	1.3404	-0.0283
762	0	CORRELATION	0.3307	0.3281	-0.0026
769	1e+12	NDD	0.7235	0.7319	0.0084
887	1e+12	NDD	1.3658	1.3611	-0.0047
891	0	CORRELATION	1.1587	1.1731	0.0144
927	1e+12	NDD	0.4206	0.4577	0.0371
967	5e+12	NDD	0.5652	0.5475	-0.0177
1204	1e+13	NDD	0.3592	0.3341	-0.0251
1284	1e+13	NDD	0.4329	0.4874	0.0545
1292	5e+12	NDD	0.898	0.9074	0.0094
1364	1e+13	NDD	1.222	1.25	0.028
1383	5e+12	NDD	1.7853	1.7918	0.0065
1388	5e+12	NDD	0.6439	0.6356	-0.0083
1427	1e+13	NDD	2.4709	2.4934	0.0225
1666	0	CORRELATION	0.6714	0.6743	0.0029

Test Statistics (mV)

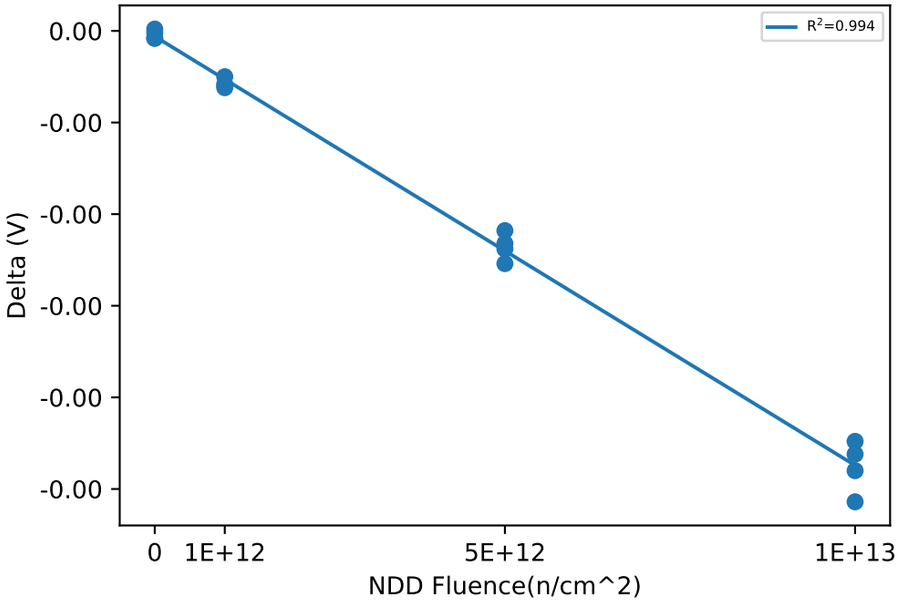
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3307	1.29	2.9994	1.1891	0.3281	1.2915	2.9904	1.1845	-0.009	0.001425	0.0144	0.0099232
1e+12	0.4206	0.96965	1.3687	0.47547	0.4577	0.97277	1.3611	0.45065	-0.0283	0.003125	0.0371	0.02727
5e+12	0.5652	0.9731	1.7853	0.55978	0.5475	0.97058	1.7918	0.56851	-0.0177	-0.002525	0.0094	0.012745
1e+13	0.3592	1.1212	2.4709	0.98086	0.3341	1.1412	2.4934	0.98643	-0.0251	0.019975	0.0545	0.033139

Device Test: 19.55 VOLTAGE|VREF//12/12/0/0/5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

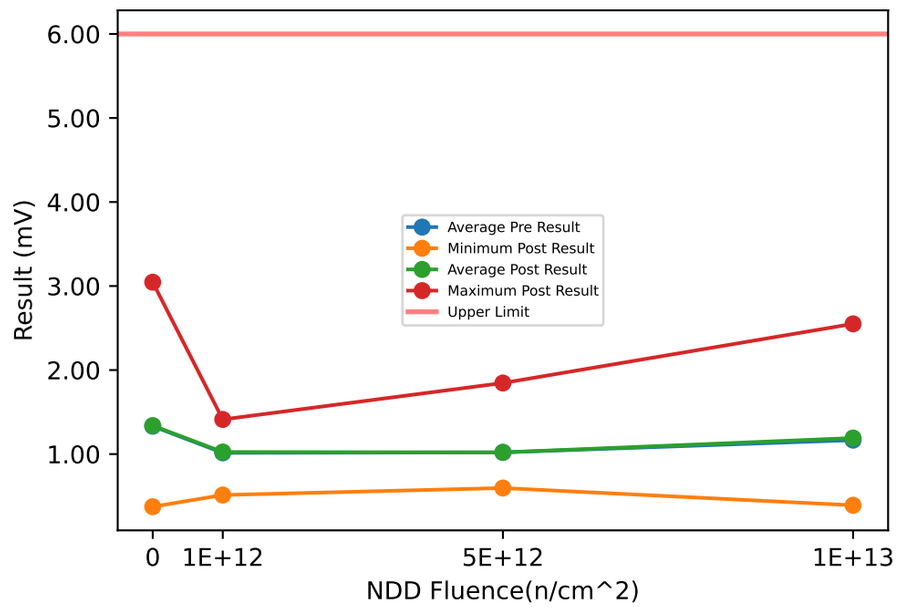
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60024	0.6002	-4e-05
466	1e+12	NDD	0.6002	0.5999	-0.0003
762	0	CORRELATION	0.59973	0.59972	-1e-05
769	1e+12	NDD	0.59987	0.59962	-0.00025
887	1e+12	NDD	0.60041	0.6001	-0.00031
891	0	CORRELATION	0.59983	0.59984	1e-05
927	1e+12	NDD	0.60036	0.60007	-0.00029
967	5e+12	NDD	0.6002	0.59893	-0.00127
1204	1e+13	NDD	0.60017	0.59777	-0.0024
1284	1e+13	NDD	0.59979	0.59748	-0.00231
1292	5e+12	NDD	0.60045	0.59929	-0.00116
1364	1e+13	NDD	0.60039	0.59782	-0.00257
1383	5e+12	NDD	0.60042	0.59933	-0.00109
1388	5e+12	NDD	0.60031	0.59912	-0.00119
1427	1e+13	NDD	0.60027	0.59803	-0.00224
1666	0	CORRELATION	0.60037	0.60033	-4e-05

Test Statistics (V)

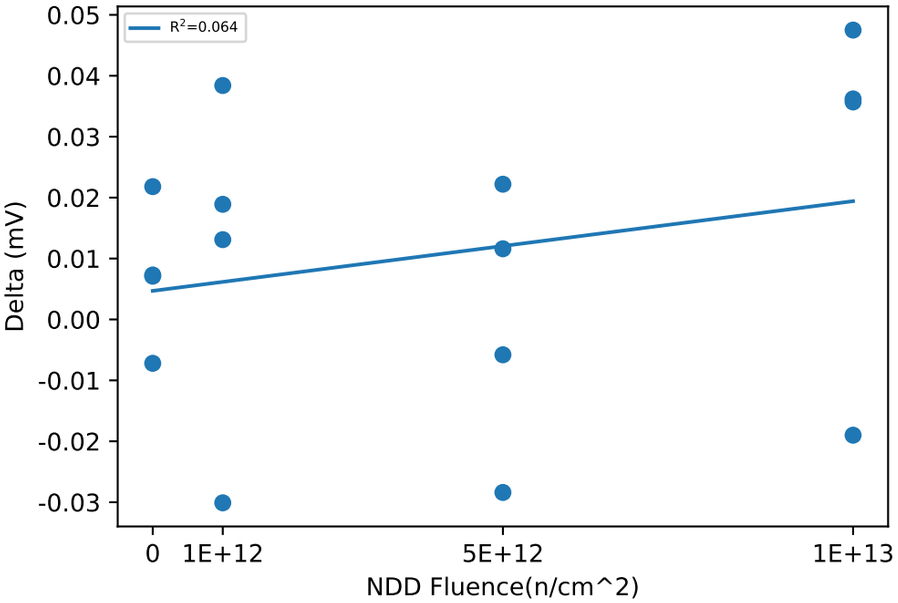
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59973	0.60004	0.60037	0.00031042	0.59972	0.60002	0.60033	0.00028918	-4e-05	-2e-05	1e-05	2.4495e-05
1e+12	0.59987	0.60021	0.60041	0.00024372	0.59962	0.59992	0.6001	0.00022006	-0.00031	-0.0002875	-0.00025	2.63e-05
5e+12	0.6002	0.60035	0.60045	0.00011387	0.59893	0.59917	0.59933	0.00018264	-0.00127	-0.0011775	-0.00109	7.4554e-05
1e+13	0.59979	0.60015	0.60039	0.00025942	0.59748	0.59777	0.59803	0.00022664	-0.00257	-0.00238	-0.00224	0.00014259

Device Test: 19.57 VOLTAGE|OFFSET//12/12/0/0/5/1MHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

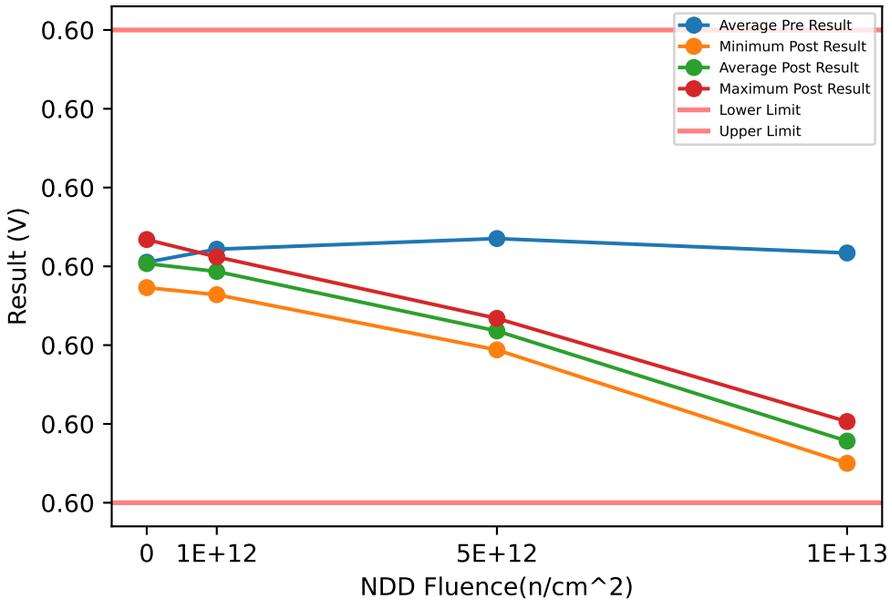
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.0386	3.0457	0.0071
466	1e+12	NDD	1.4235	1.3934	-0.0301
762	0	CORRELATION	0.3662	0.3735	0.0073
769	1e+12	NDD	0.767	0.7801	0.0131
887	1e+12	NDD	1.3933	1.4122	0.0189
891	0	CORRELATION	1.2023	1.2241	0.0218
927	1e+12	NDD	0.4743	0.5127	0.0384
967	5e+12	NDD	0.6016	0.5958	-0.0058
1204	1e+13	NDD	0.4099	0.3909	-0.019
1284	1e+13	NDD	0.4842	0.5317	0.0475
1292	5e+12	NDD	0.9517	0.9633	0.0116
1364	1e+13	NDD	1.2552	1.2914	0.0362
1383	5e+12	NDD	1.8236	1.8458	0.0222
1388	5e+12	NDD	0.7042	0.6758	-0.0284
1427	1e+13	NDD	2.5142	2.5499	0.0357
1666	0	CORRELATION	0.7203	0.7131	-0.0072

Test Statistics (mV)

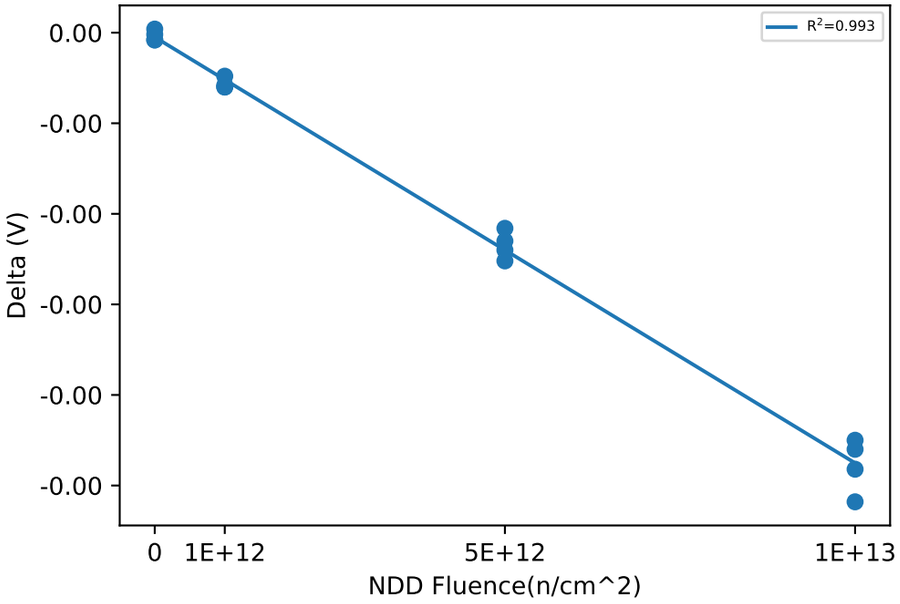
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3662	1.3318	3.0386	1.1883	0.3735	1.3391	3.0457	1.1902	-0.0072	0.00725	0.0218	0.01184
1e+12	0.4743	1.0145	1.4235	0.47041	0.5127	1.0246	1.4122	0.45021	-0.0301	0.010075	0.0384	0.028887
5e+12	0.6016	1.0203	1.8236	0.55535	0.5958	1.0202	1.8458	0.57259	-0.0284	-0.0001	0.0222	0.022118
1e+13	0.4099	1.1659	2.5142	0.97675	0.3909	1.191	2.5499	0.98852	-0.019	0.0251	0.0475	0.029901

Device Test: 19.58 VOLTAGE|VREF//14/14/0/0/5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



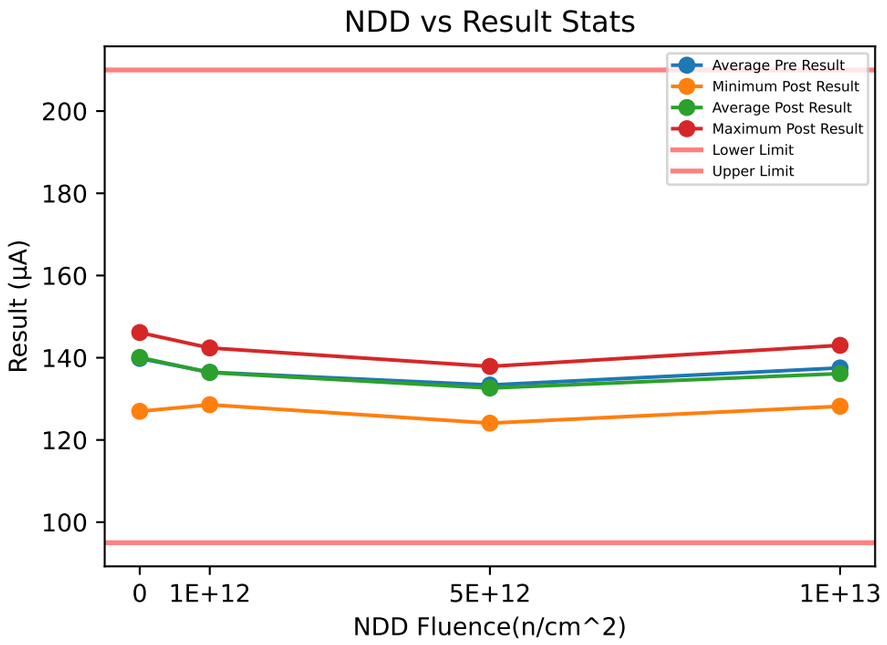
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

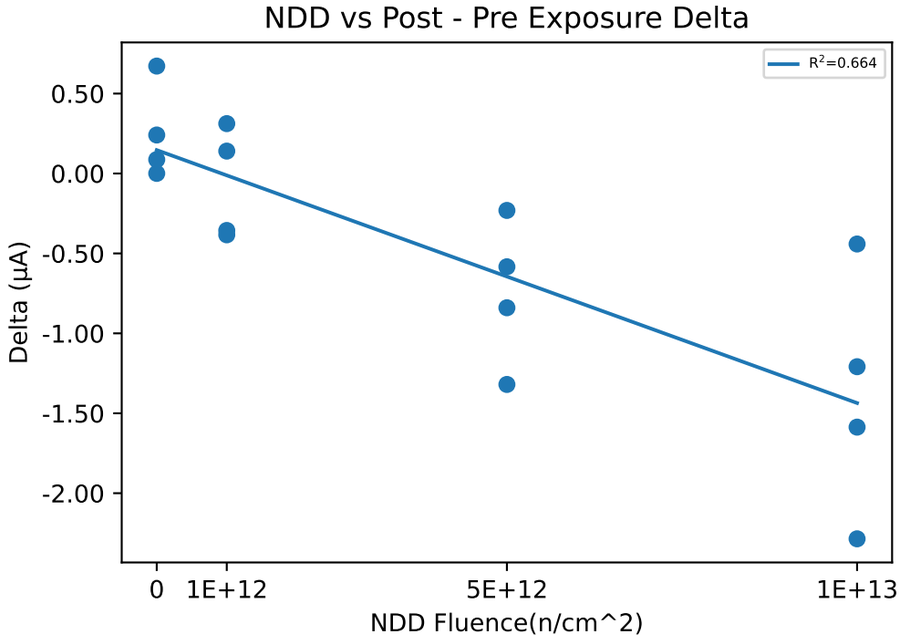
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60025	0.60021	-4e-05
466	1e+12	NDD	0.6002	0.59991	-0.00029
762	0	CORRELATION	0.59974	0.59973	-1e-05
769	1e+12	NDD	0.59988	0.59964	-0.00024
887	1e+12	NDD	0.60042	0.60012	-0.0003
891	0	CORRELATION	0.59984	0.59986	2e-05
927	1e+12	NDD	0.60037	0.60007	-0.0003
967	5e+12	NDD	0.6002	0.59894	-0.00126
1204	1e+13	NDD	0.60019	0.59778	-0.00241
1284	1e+13	NDD	0.5998	0.5975	-0.0023
1292	5e+12	NDD	0.60046	0.59931	-0.00115
1364	1e+13	NDD	0.60041	0.59782	-0.00259
1383	5e+12	NDD	0.60042	0.59934	-0.00108
1388	5e+12	NDD	0.60033	0.59913	-0.0012
1427	1e+13	NDD	0.60028	0.59803	-0.00225
1666	0	CORRELATION	0.60038	0.60034	-4e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59974	0.60005	0.60038	0.00031042	0.59973	0.60003	0.60034	0.00028711	-4e-05	-1.75e-05	2e-05	2.8723e-05
1e+12	0.59988	0.60022	0.60042	0.00024391	0.59964	0.59993	0.60012	0.0002161	-0.0003	-0.0002825	-0.00024	2.8723e-05
5e+12	0.6002	0.60035	0.60046	0.00011529	0.59894	0.59918	0.59934	0.00018493	-0.00126	-0.0011725	-0.00108	7.6322e-05
1e+13	0.5998	0.60017	0.60041	0.00026268	0.5975	0.59778	0.59803	0.00021793	-0.00259	-0.0023875	-0.00225	0.00015064

Device Test: 19.6 CURRENT|EA_SOURCE//5/5/0/0/5/500kHz//@EA_I_SOURCE





Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

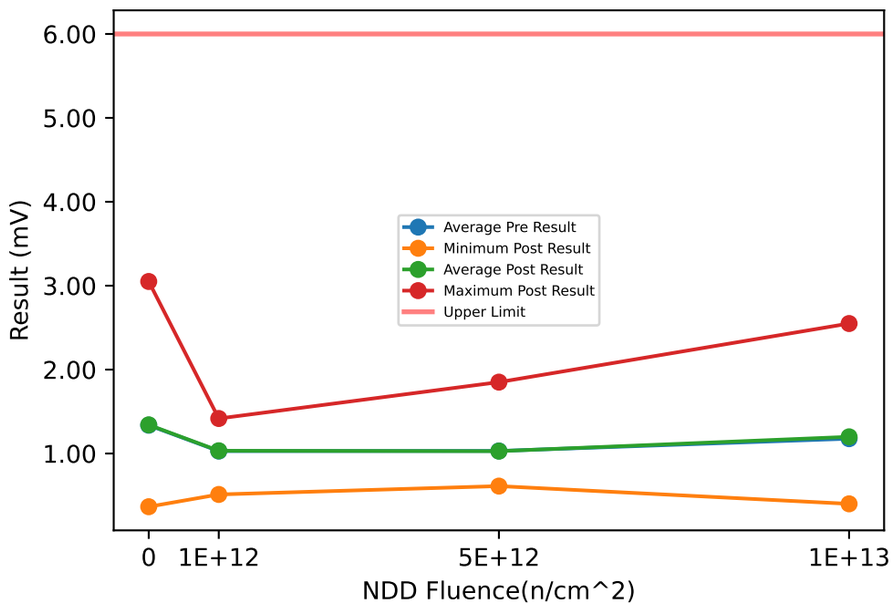
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	144.4	144.4	0.0006
466	1e+12	NDD	142.07	142.38	0.312
762	0	CORRELATION	145.89	146.13	0.2408
769	1e+12	NDD	128.43	128.57	0.1401
887	1e+12	NDD	136.53	136.14	-0.3836
891	0	CORRELATION	126.88	126.97	0.0871
927	1e+12	NDD	138.84	138.49	-0.3564
967	5e+12	NDD	138.48	137.89	-0.5835
1204	1e+13	NDD	134.89	134.45	-0.4411
1284	1e+13	NDD	130.48	128.19	-2.2854
1292	5e+12	NDD	136.68	135.36	-1.3197
1364	1e+13	NDD	144.6	143.01	-1.5867
1383	5e+12	NDD	133.98	133.14	-0.8399
1388	5e+12	NDD	124.32	124.09	-0.231
1427	1e+13	NDD	140.11	138.9	-1.2087
1666	0	CORRELATION	142.18	142.85	0.672

Test Statistics (µA)

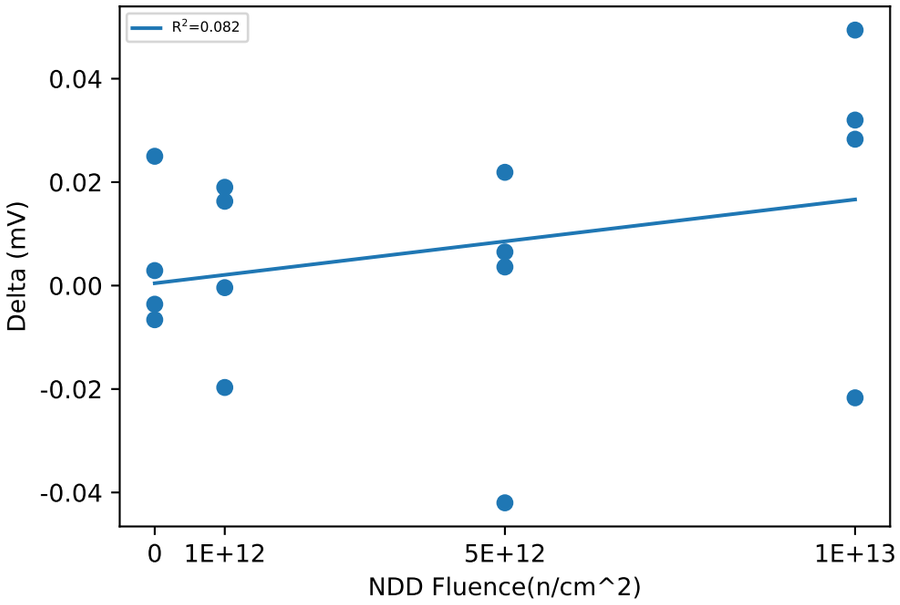
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	126.88	139.84	145.89	8.7708	126.97	140.09	146.13	8.8481	0.0006	0.25012	0.672	0.29828
1e+12	128.43	136.47	142.07	5.8225	128.57	136.39	142.38	5.8189	-0.3836	-0.071975	0.312	0.35139
5e+12	124.32	133.36	138.48	6.3064	124.09	132.62	137.89	6.0102	-1.3197	-0.74353	-0.231	0.4581
1e+13	130.48	137.52	144.6	6.1472	128.19	136.14	143.01	6.3483	-2.2854	-1.3805	-0.4411	0.76884

Device Test: 19.60 VOLTAGE|OFFSET//14/14/0/0/5/1MHz//@EA_OS

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 6.0 (mV))

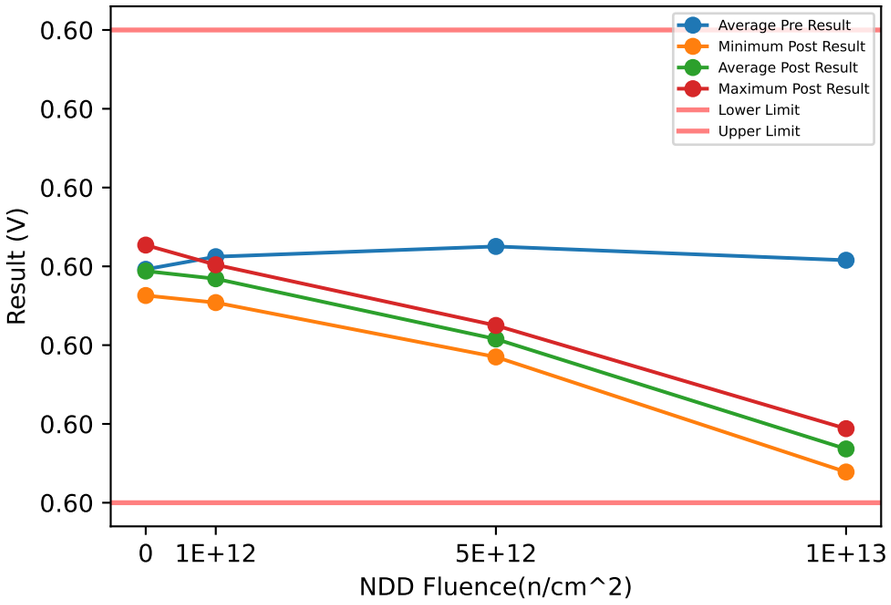
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.0538	3.0502	-0.0036
466	1e+12	NDD	1.4202	1.4005	-0.0197
762	0	CORRELATION	0.363	0.3659	0.0029
769	1e+12	NDD	0.782	0.801	0.019
887	1e+12	NDD	1.4176	1.4172	-0.0004
891	0	CORRELATION	1.2127	1.2377	0.025
927	1e+12	NDD	0.4957	0.512	0.0163
967	5e+12	NDD	0.608	0.6116	0.0036
1204	1e+13	NDD	0.422	0.4003	-0.0217
1284	1e+13	NDD	0.4986	0.548	0.0494
1292	5e+12	NDD	0.9637	0.9702	0.0065
1364	1e+13	NDD	1.2658	1.2978	0.032
1383	5e+12	NDD	1.8288	1.8507	0.0219
1388	5e+12	NDD	0.7221	0.6801	-0.042
1427	1e+13	NDD	2.5208	2.5491	0.0283
1666	0	CORRELATION	0.7196	0.713	-0.0066

Test Statistics (mV)

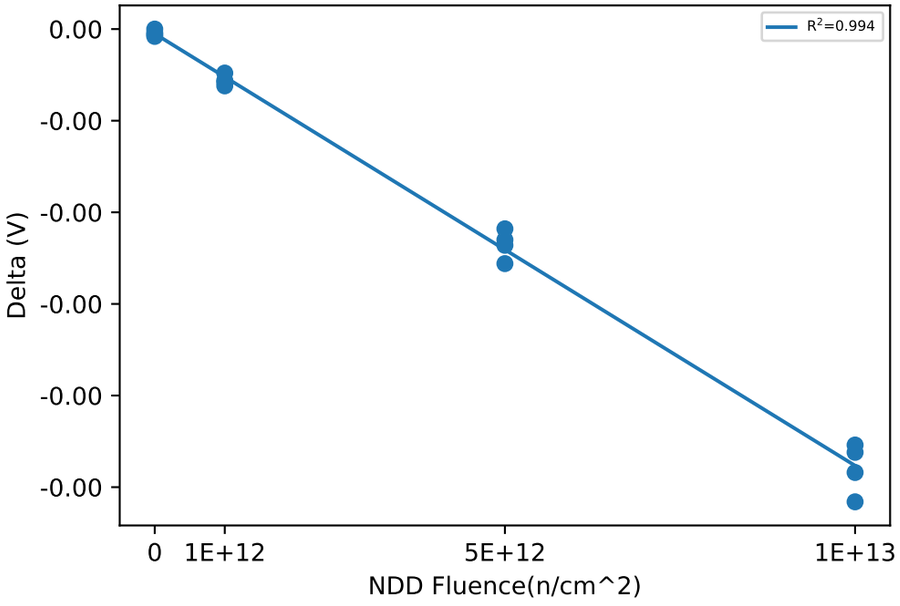
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.363	1.3373	3.0538	1.1962	0.3659	1.3417	3.0502	1.194	-0.0066	0.004425	0.025	0.014278
1e+12	0.4957	1.0289	1.4202	0.46528	0.512	1.0327	1.4172	0.45016	-0.0197	0.0038	0.019	0.017862
5e+12	0.608	1.0307	1.8288	0.55238	0.6116	1.0282	1.8507	0.56997	-0.042	-0.0025	0.0219	0.027531
1e+13	0.422	1.1768	2.5208	0.97364	0.4003	1.1988	2.5491	0.98222	-0.0217	0.022	0.0494	0.030551

Device Test: 19.61 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

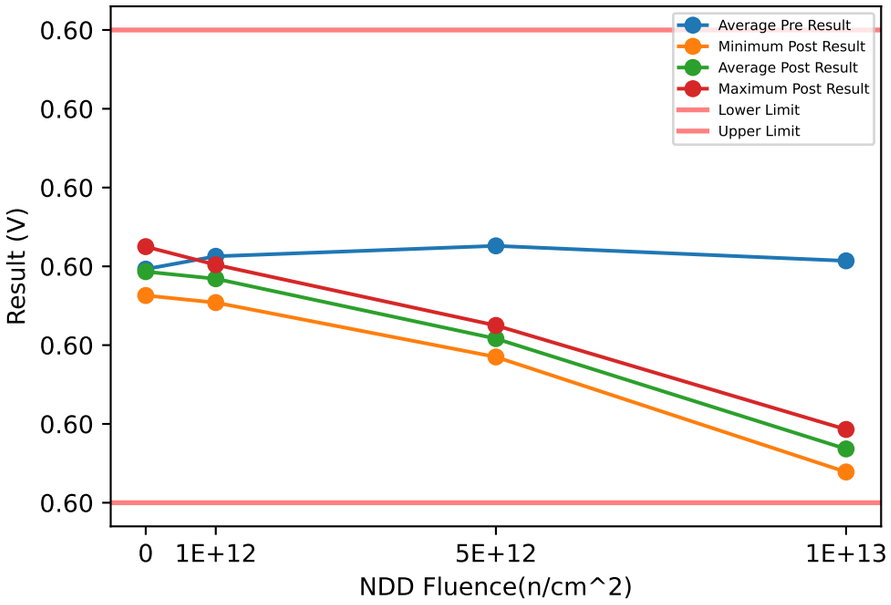
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60014	0.60011	-3e-05
466	1e+12	NDD	0.60011	0.59982	-0.00029
762	0	CORRELATION	0.59965	0.59963	-2e-05
769	1e+12	NDD	0.59978	0.59954	-0.00024
887	1e+12	NDD	0.60033	0.60002	-0.00031
891	0	CORRELATION	0.59975	0.59975	0
927	1e+12	NDD	0.60027	0.59999	-0.00028
967	5e+12	NDD	0.60013	0.59885	-0.00128
1204	1e+13	NDD	0.60008	0.59766	-0.00242
1284	1e+13	NDD	0.5997	0.59739	-0.00231
1292	5e+12	NDD	0.60033	0.59918	-0.00115
1364	1e+13	NDD	0.60032	0.59774	-0.00258
1383	5e+12	NDD	0.60034	0.59925	-0.00109
1388	5e+12	NDD	0.60021	0.59903	-0.00118
1427	1e+13	NDD	0.60021	0.59794	-0.00227
1666	0	CORRELATION	0.60031	0.60027	-4e-05

Test Statistics (V)

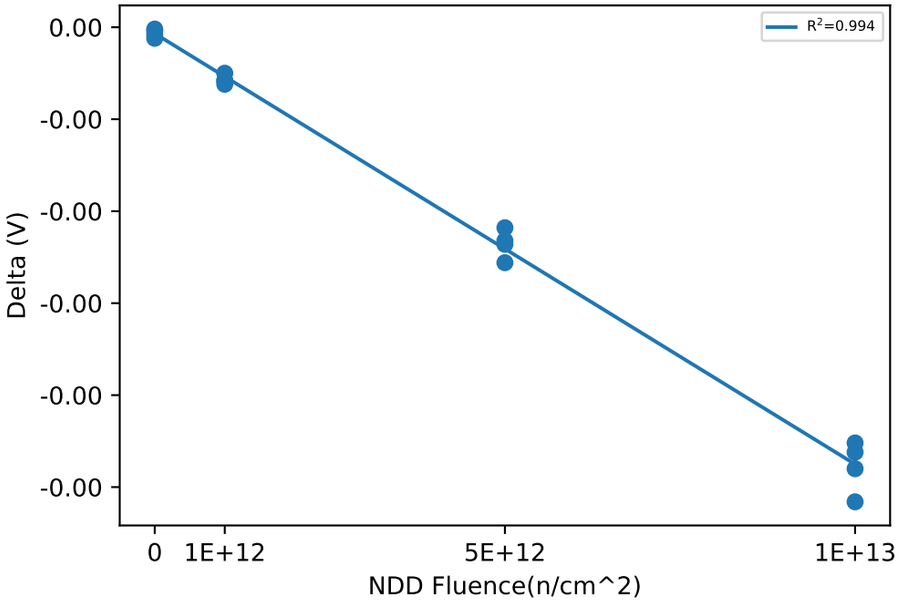
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59965	0.59996	0.60031	0.00031362	0.59963	0.59994	0.60027	0.0003	-4e-05	-2.25e-05	0	1.7078e-05
1e+12	0.59978	0.60012	0.60033	0.00024649	0.59954	0.59984	0.60002	0.00022006	-0.00031	-0.00028	-0.00024	2.9439e-05
5e+12	0.60013	0.60025	0.60034	0.00010079	0.59885	0.59908	0.59925	0.00017727	-0.00128	-0.001175	-0.00109	7.9373e-05
1e+13	0.5997	0.60008	0.60032	0.00027011	0.59739	0.59768	0.59794	0.0002278	-0.00258	-0.002395	-0.00227	0.00013868

Device Test: 19.63 VOLTAGE|VREF//5/5/0/1000/5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

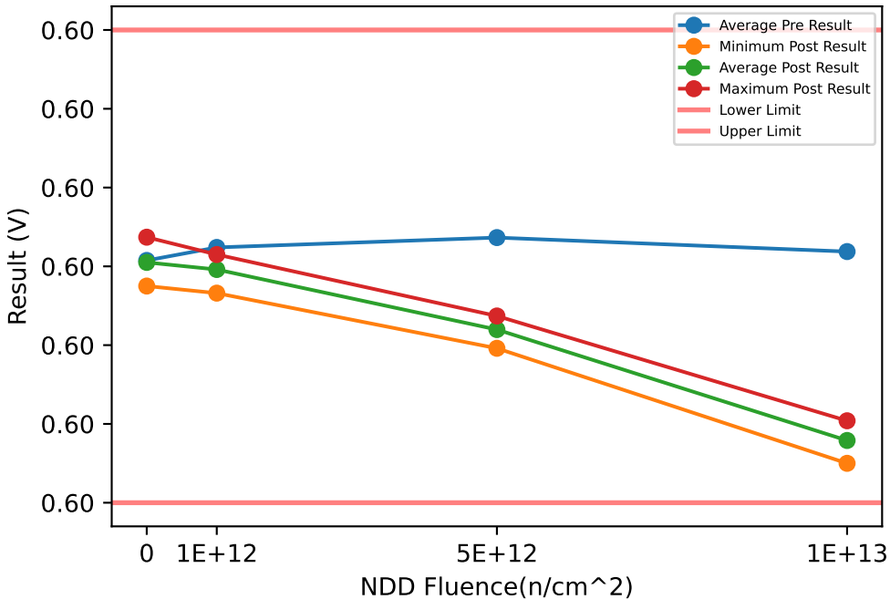
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60015	0.60011	-4e-05
466	1e+12	NDD	0.60011	0.59982	-0.00029
762	0	CORRELATION	0.59965	0.59963	-2e-05
769	1e+12	NDD	0.59979	0.59954	-0.00025
887	1e+12	NDD	0.60033	0.60002	-0.00031
891	0	CORRELATION	0.59975	0.59974	-1e-05
927	1e+12	NDD	0.60028	0.59999	-0.00029
967	5e+12	NDD	0.60013	0.59885	-0.00128
1204	1e+13	NDD	0.60007	0.59767	-0.0024
1284	1e+13	NDD	0.5997	0.59739	-0.00231
1292	5e+12	NDD	0.60035	0.59919	-0.00116
1364	1e+13	NDD	0.60032	0.59774	-0.00258
1383	5e+12	NDD	0.60034	0.59925	-0.00109
1388	5e+12	NDD	0.60022	0.59904	-0.00118
1427	1e+13	NDD	0.60019	0.59793	-0.00226
1666	0	CORRELATION	0.60031	0.60025	-6e-05

Test Statistics (V)

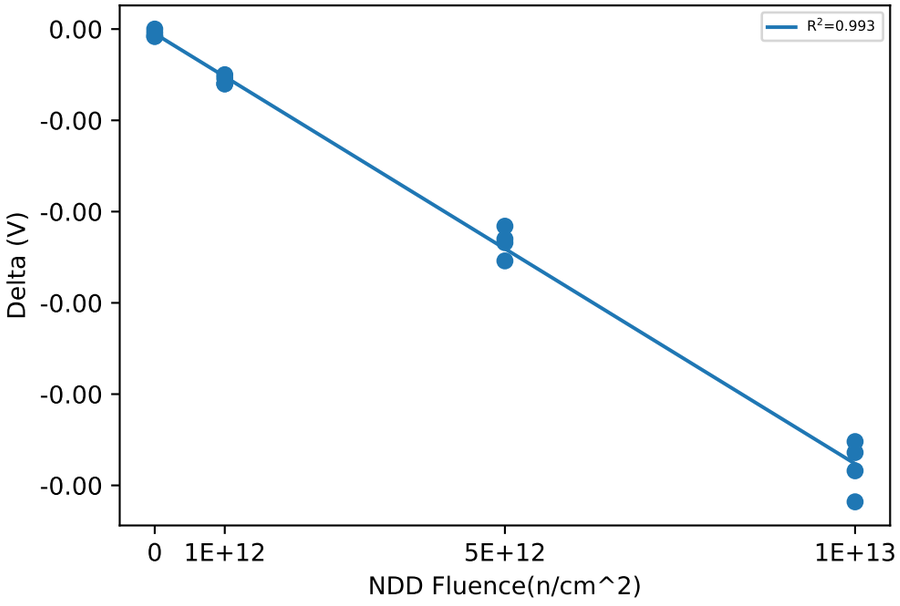
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59965	0.59996	0.60031	0.00031554	0.59963	0.59993	0.60025	0.00029489	-6e-05	-3.25e-05	-1e-05	2.2174e-05
1e+12	0.59979	0.60013	0.60033	0.00024391	0.59954	0.59984	0.60002	0.00022006	-0.00031	-0.000285	-0.00025	2.5166e-05
5e+12	0.60013	0.60026	0.60035	0.00010488	0.59885	0.59908	0.59925	0.0001784	-0.00128	-0.0011775	-0.00109	7.8475e-05
1e+13	0.5997	0.60007	0.60032	0.00026696	0.59739	0.59768	0.59793	0.00022381	-0.00258	-0.0023875	-0.00226	0.0001408

Device Test: 19.65 VOLTAGE|VREF//12/12/0/1000/5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

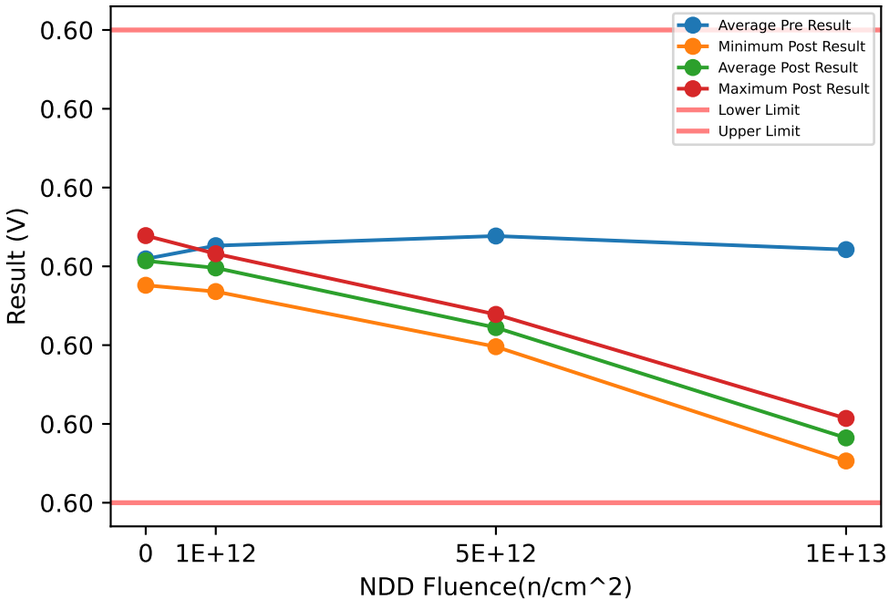
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60026	0.60022	-4e-05
466	1e+12	NDD	0.60023	0.59993	-0.0003
762	0	CORRELATION	0.59977	0.59975	-2e-05
769	1e+12	NDD	0.59991	0.59966	-0.00025
887	1e+12	NDD	0.60045	0.60015	-0.0003
891	0	CORRELATION	0.59986	0.59986	0
927	1e+12	NDD	0.60037	0.6001	-0.00027
967	5e+12	NDD	0.60023	0.59896	-0.00127
1204	1e+13	NDD	0.6002	0.59778	-0.00242
1284	1e+13	NDD	0.59982	0.5975	-0.00232
1292	5e+12	NDD	0.60045	0.5993	-0.00115
1364	1e+13	NDD	0.60043	0.59784	-0.00259
1383	5e+12	NDD	0.60045	0.59937	-0.00108
1388	5e+12	NDD	0.60033	0.59916	-0.00117
1427	1e+13	NDD	0.6003	0.59804	-0.00226
1666	0	CORRELATION	0.60041	0.60037	-4e-05

Test Statistics (V)

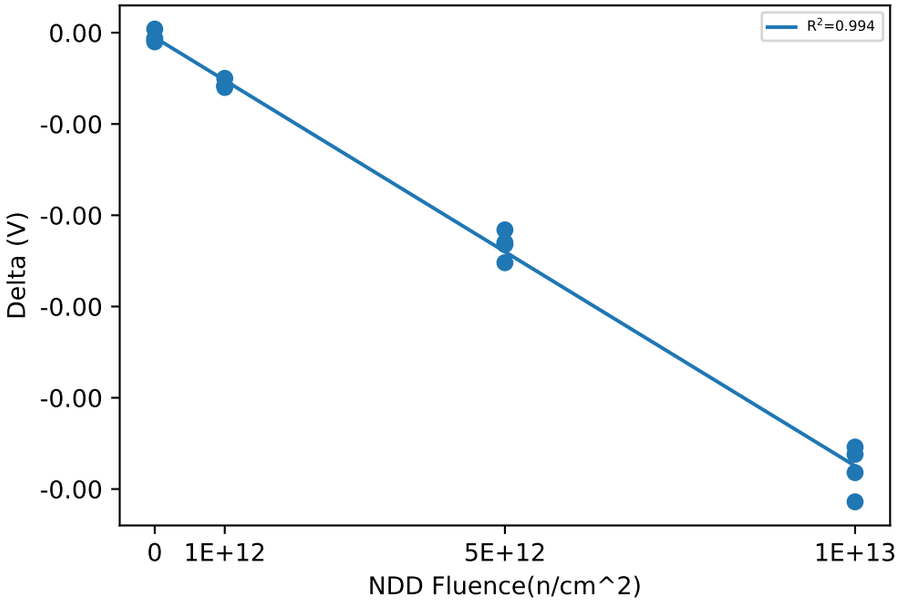
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59977	0.60008	0.60041	0.0003086	0.59975	0.60005	0.60037	0.00029292	-4e-05	-2.5e-05	0	1.9149e-05
1e+12	0.59991	0.60024	0.60045	0.00023805	0.59966	0.59996	0.60015	0.00022106	-0.0003	-0.00028	-0.00025	2.4495e-05
5e+12	0.60023	0.60037	0.60045	0.0001063	0.59896	0.5992	0.59937	0.00018081	-0.00127	-0.0011675	-0.00108	7.8475e-05
1e+13	0.59982	0.60019	0.60043	0.00026247	0.5975	0.59779	0.59804	0.00022301	-0.00259	-0.0023975	-0.00226	0.00014431

Device Test: 19.67 VOLTAGE|VREF//14/14/0/1000/5/100kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

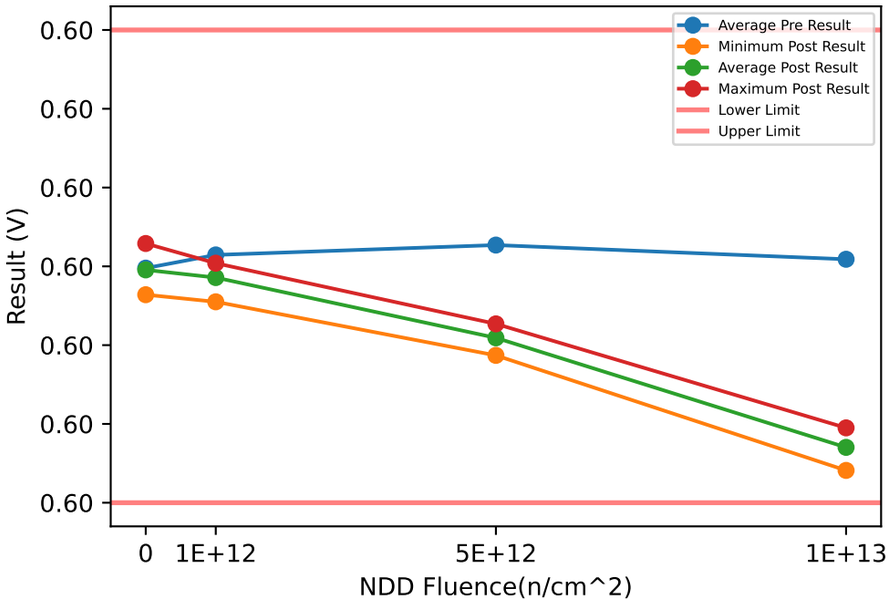
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60029	0.60024	-5e-05
466	1e+12	NDD	0.60025	0.59996	-0.00029
762	0	CORRELATION	0.59979	0.59976	-3e-05
769	1e+12	NDD	0.59993	0.59968	-0.00025
887	1e+12	NDD	0.60046	0.60016	-0.0003
891	0	CORRELATION	0.59987	0.59989	2e-05
927	1e+12	NDD	0.60041	0.60012	-0.00029
967	5e+12	NDD	0.60024	0.59898	-0.00126
1204	1e+13	NDD	0.60022	0.59781	-0.00241
1284	1e+13	NDD	0.59984	0.59753	-0.00231
1292	5e+12	NDD	0.60048	0.59933	-0.00115
1364	1e+13	NDD	0.60045	0.59788	-0.00257
1383	5e+12	NDD	0.60047	0.59939	-0.00108
1388	5e+12	NDD	0.60035	0.59919	-0.00116
1427	1e+13	NDD	0.60034	0.59807	-0.00227
1666	0	CORRELATION	0.60043	0.60039	-4e-05

Test Statistics (V)

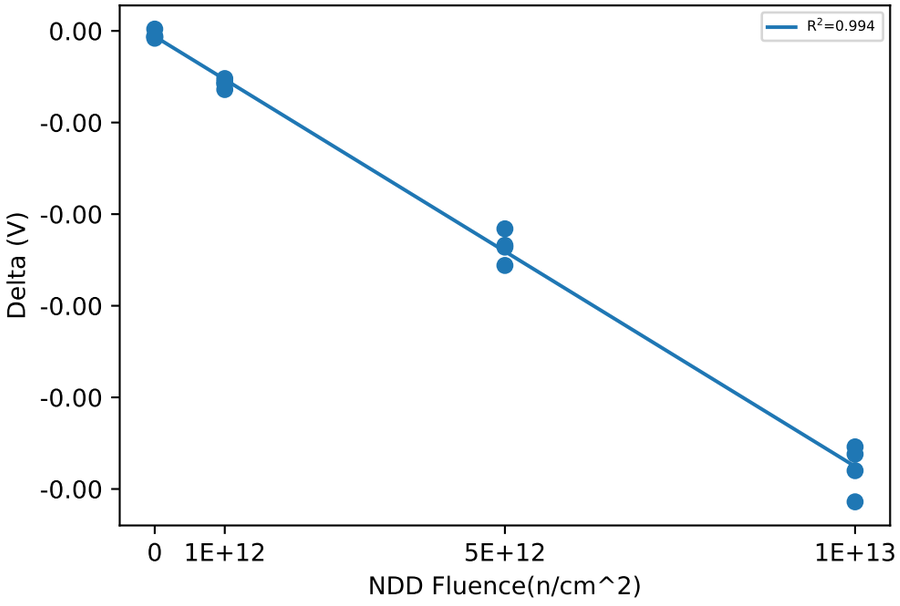
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59979	0.6001	0.60043	0.000313	0.59976	0.60007	0.60039	0.00029428	-5e-05	-2.5e-05	2e-05	3.1091e-05
1e+12	0.59993	0.60026	0.60046	0.00023908	0.59968	0.59998	0.60016	0.00021787	-0.0003	-0.0002825	-0.00025	2.2174e-05
5e+12	0.60024	0.60038	0.60048	0.00011328	0.59898	0.59922	0.59939	0.00018209	-0.00126	-0.0011625	-0.00108	7.4106e-05
1e+13	0.59984	0.60021	0.60045	0.0002655	0.59753	0.59782	0.59807	0.00022381	-0.00257	-0.00239	-0.00227	0.00013367

Device Test: 19.69 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

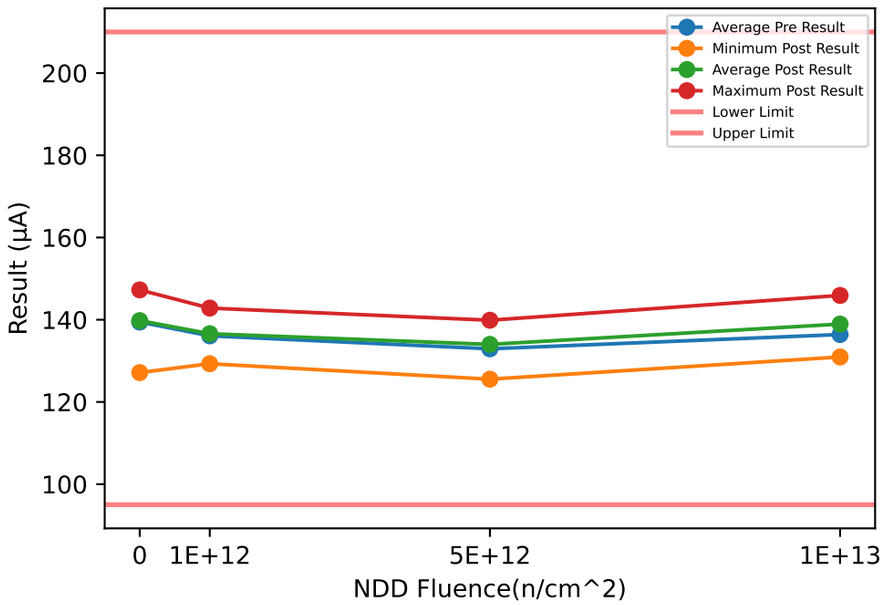
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60016	0.60012	-4e-05
466	1e+12	NDD	0.60012	0.59983	-0.00029
762	0	CORRELATION	0.59967	0.59964	-3e-05
769	1e+12	NDD	0.59981	0.59955	-0.00026
887	1e+12	NDD	0.60036	0.60004	-0.00032
891	0	CORRELATION	0.59976	0.59977	1e-05
927	1e+12	NDD	0.60029	0.60001	-0.00028
967	5e+12	NDD	0.60015	0.59887	-0.00128
1204	1e+13	NDD	0.60009	0.59769	-0.0024
1284	1e+13	NDD	0.59972	0.59741	-0.00231
1292	5e+12	NDD	0.60036	0.59919	-0.00117
1364	1e+13	NDD	0.60033	0.59776	-0.00257
1383	5e+12	NDD	0.60035	0.59927	-0.00108
1388	5e+12	NDD	0.60022	0.59904	-0.00118
1427	1e+13	NDD	0.60022	0.59795	-0.00227
1666	0	CORRELATION	0.60032	0.60029	-3e-05

Test Statistics (V)

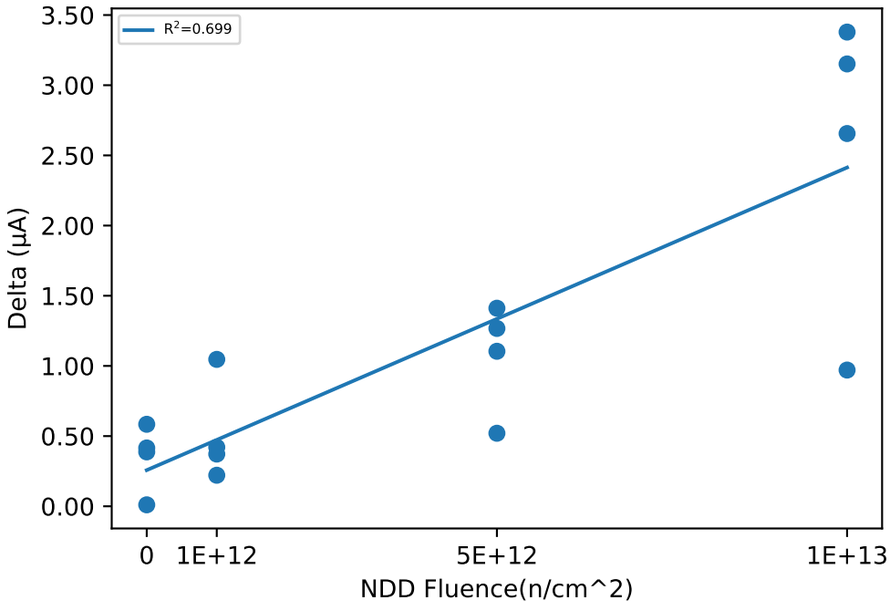
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59967	0.59998	0.60032	0.00031224	0.59964	0.59996	0.60029	0.00030161	-4e-05	-2.25e-05	1e-05	2.2174e-05
1e+12	0.59981	0.60014	0.60036	0.00024502	0.59955	0.59986	0.60004	0.000225	-0.00032	-0.0002875	-0.00026	2.5e-05
5e+12	0.60015	0.60027	0.60036	0.00010231	0.59887	0.59909	0.59927	0.00017633	-0.00128	-0.0011775	-0.00108	8.1803e-05
1e+13	0.59972	0.60009	0.60033	0.00026546	0.59741	0.5977	0.59795	0.00022381	-0.00257	-0.0023875	-0.00227	0.00013326

Device Test: 19.7 CURRENT|EA_SINK//5/5/0/0/5/500kHz//@EA_I_SINK

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 95.0, Upper Limit = 210.0 (µA))

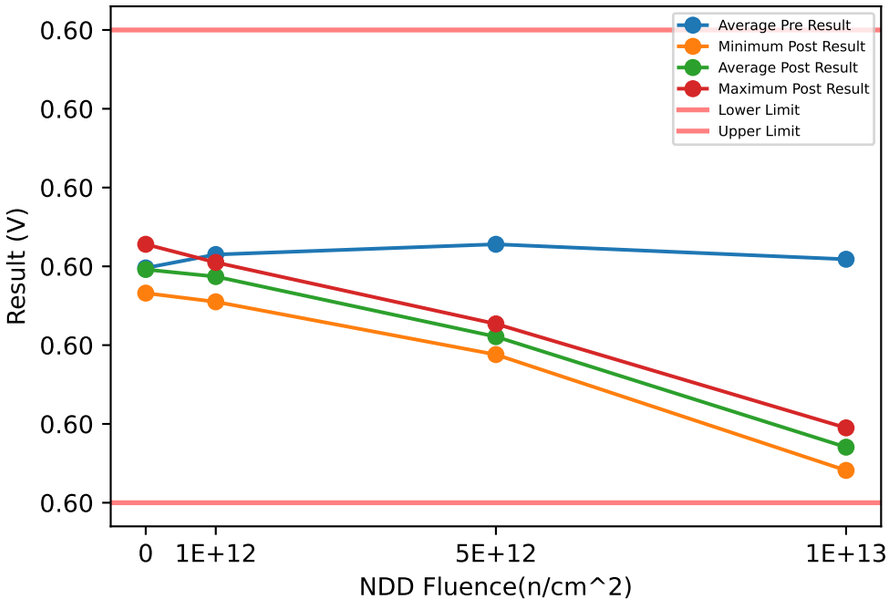
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	142.51	142.92	0.4155
466	1e+12	NDD	141.78	142.83	1.0466
762	0	CORRELATION	146.68	147.26	0.5842
769	1e+12	NDD	128.88	129.3	0.4206
887	1e+12	NDD	135.06	135.28	0.2212
891	0	CORRELATION	127.13	127.14	0.0104
927	1e+12	NDD	138.62	138.99	0.372
967	5e+12	NDD	138.61	139.88	1.2671
1204	1e+13	NDD	134.66	138.04	3.3786
1284	1e+13	NDD	129.97	130.94	0.9705
1292	5e+12	NDD	136.55	137.07	0.5203
1364	1e+13	NDD	142.76	145.91	3.1516
1383	5e+12	NDD	132.42	133.52	1.1044
1388	5e+12	NDD	124.13	125.54	1.4111
1427	1e+13	NDD	138.23	140.88	2.6557
1666	0	CORRELATION	141.44	141.83	0.3875

Test Statistics (µA)

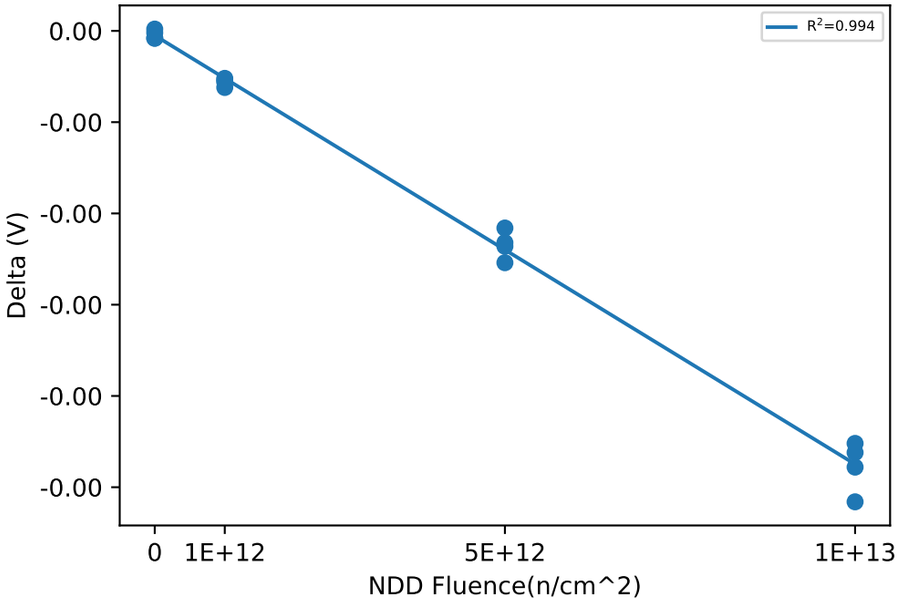
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	127.13	139.44	146.68	8.512	127.14	139.79	147.26	8.753	0.0104	0.3494	0.5842	0.24212
1e+12	128.88	136.08	141.78	5.5357	129.3	136.6	142.83	5.7628	0.2212	0.5151	1.0466	0.36436
5e+12	124.13	132.93	138.61	6.4071	125.54	134	139.88	6.2138	0.5203	1.0757	1.4111	0.3909
1e+13	129.97	136.41	142.76	5.4197	130.94	138.94	145.91	6.2488	0.9705	2.5391	3.3786	1.0884

Device Test: 19.71 VOLTAGE|VREF//5/5/0/1000/5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

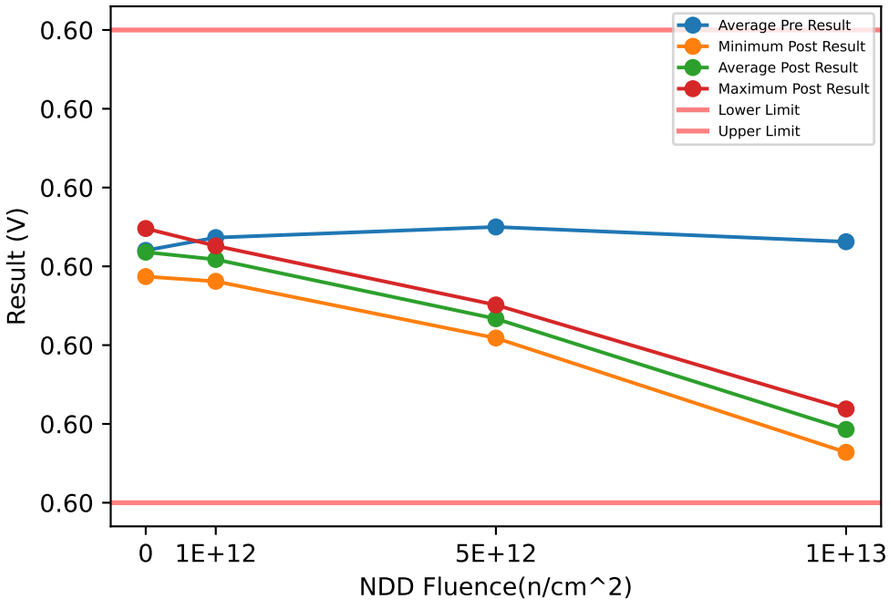
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60017	0.60013	-4e-05
466	1e+12	NDD	0.60013	0.59985	-0.00028
762	0	CORRELATION	0.59967	0.59966	-1e-05
769	1e+12	NDD	0.59981	0.59955	-0.00026
887	1e+12	NDD	0.60036	0.60005	-0.00031
891	0	CORRELATION	0.59976	0.59977	1e-05
927	1e+12	NDD	0.6003	0.60003	-0.00027
967	5e+12	NDD	0.60015	0.59888	-0.00127
1204	1e+13	NDD	0.60009	0.5977	-0.00239
1284	1e+13	NDD	0.59972	0.59741	-0.00231
1292	5e+12	NDD	0.60038	0.59922	-0.00116
1364	1e+13	NDD	0.60034	0.59776	-0.00258
1383	5e+12	NDD	0.60035	0.59927	-0.00108
1388	5e+12	NDD	0.60024	0.59906	-0.00118
1427	1e+13	NDD	0.60021	0.59795	-0.00226
1666	0	CORRELATION	0.60032	0.60028	-4e-05

Test Statistics (V)

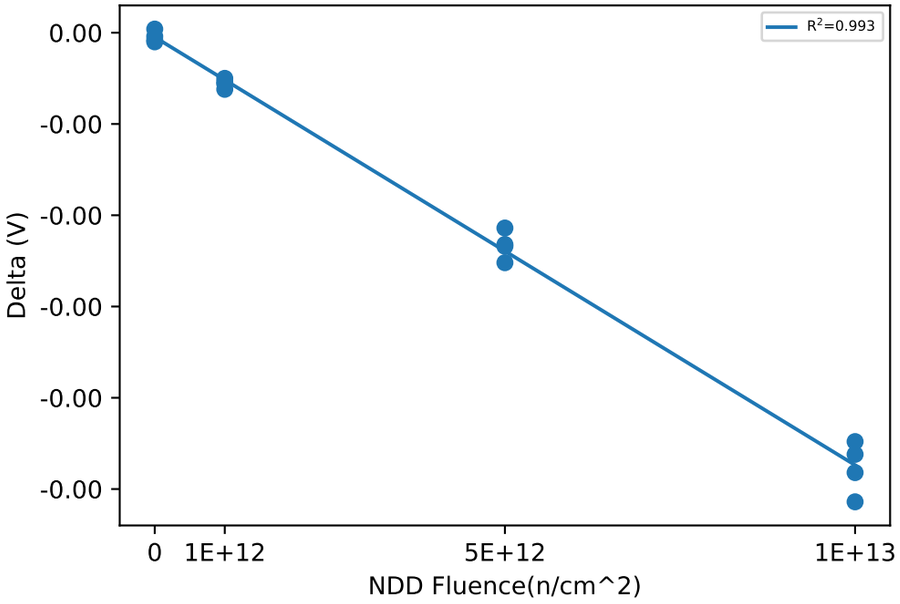
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59967	0.59998	0.60032	0.00031422	0.59966	0.59996	0.60028	0.00029292	-4e-05	-2e-05	1e-05	2.4495e-05
1e+12	0.59981	0.60015	0.60036	0.00024671	0.59955	0.59987	0.60005	0.00023152	-0.00031	-0.00028	-0.00026	2.1602e-05
5e+12	0.60015	0.60028	0.60038	0.00010551	0.59888	0.59911	0.59927	0.00017614	-0.00127	-0.0011725	-0.00108	7.8049e-05
1e+13	0.59972	0.60009	0.60034	0.00026696	0.59741	0.5977	0.59795	0.00022368	-0.00258	-0.002385	-0.00226	0.00014059

Device Test: 19.73 VOLTAGE|VREF//12/12/0/1000/5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

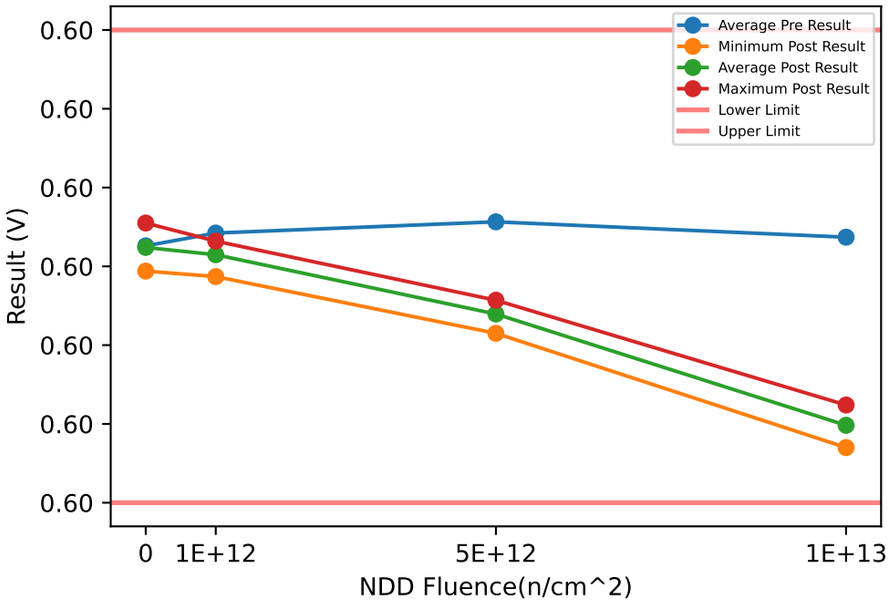
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6004	0.60035	-5e-05
466	1e+12	NDD	0.60033	0.60006	-0.00027
762	0	CORRELATION	0.59989	0.59987	-2e-05
769	1e+12	NDD	0.60006	0.59981	-0.00025
887	1e+12	NDD	0.60057	0.60026	-0.00031
891	0	CORRELATION	0.6	0.60002	2e-05
927	1e+12	NDD	0.6005	0.60022	-0.00028
967	5e+12	NDD	0.60035	0.59909	-0.00126
1204	1e+13	NDD	0.60033	0.59792	-0.00241
1284	1e+13	NDD	0.59995	0.59764	-0.00231
1292	5e+12	NDD	0.60059	0.59943	-0.00116
1364	1e+13	NDD	0.60054	0.59797	-0.00257
1383	5e+12	NDD	0.60058	0.59951	-0.00107
1388	5e+12	NDD	0.60048	0.59931	-0.00117
1427	1e+13	NDD	0.60043	0.59819	-0.00224
1666	0	CORRELATION	0.60052	0.60048	-4e-05

Test Statistics (V)

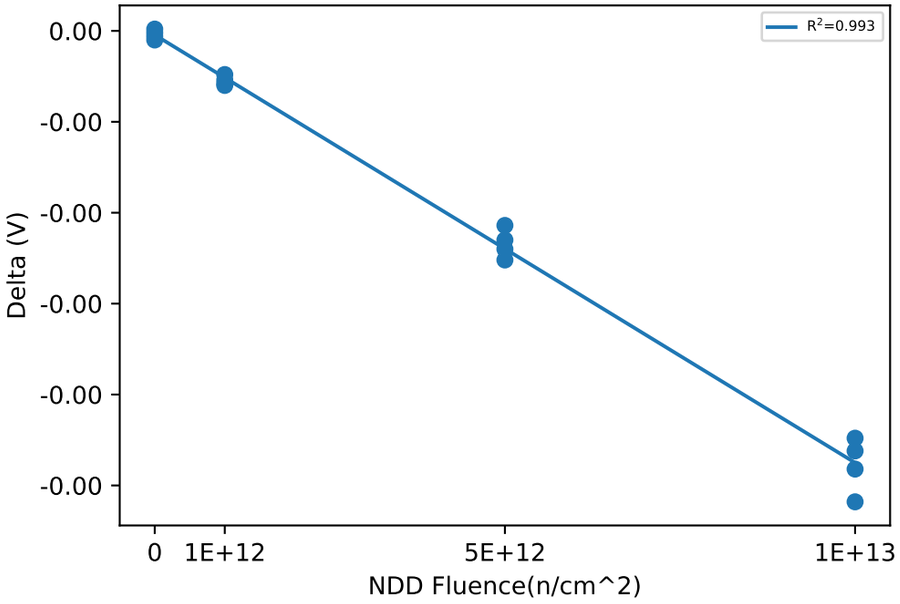
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59989	0.6002	0.60052	0.00030467	0.59987	0.60018	0.60048	0.0002832	-5e-05	-2.25e-05	2e-05	3.0957e-05
1e+12	0.60006	0.60037	0.60057	0.00022694	0.59981	0.60009	0.60026	0.00020419	-0.00031	-0.0002775	-0.00025	2.5e-05
5e+12	0.60035	0.6005	0.60059	0.00011165	0.59909	0.59933	0.59951	0.00018285	-0.00126	-0.001165	-0.00107	7.7675e-05
1e+13	0.59995	0.60031	0.60054	0.00025643	0.59764	0.59793	0.59819	0.00022613	-0.00257	-0.0023825	-0.00224	0.00014315

Device Test: 19.75 VOLTAGE|VREF//14/14/0/1000/5/500kHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

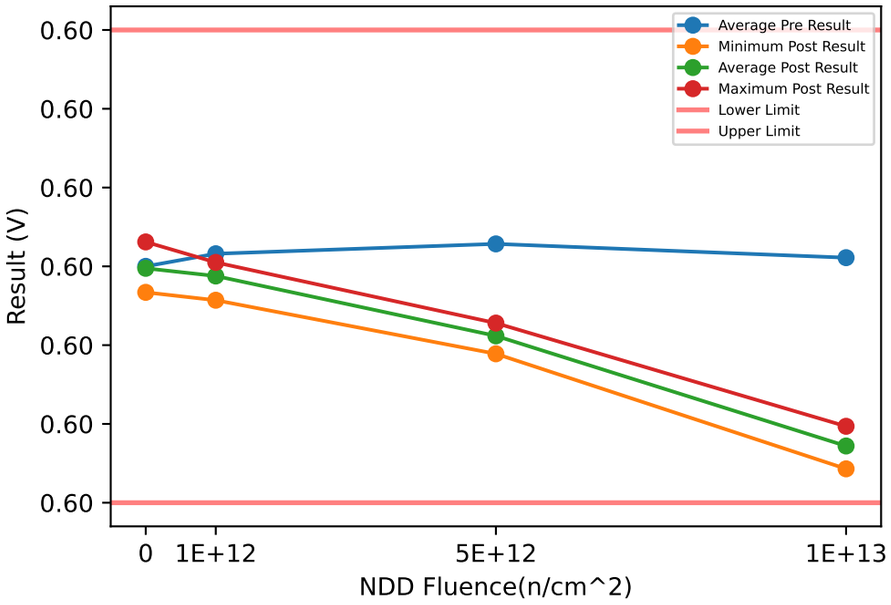
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60045	0.6004	-5e-05
466	1e+12	NDD	0.60041	0.60012	-0.00029
762	0	CORRELATION	0.59995	0.59994	-1e-05
769	1e+12	NDD	0.60011	0.59987	-0.00024
887	1e+12	NDD	0.60062	0.60032	-0.0003
891	0	CORRELATION	0.60006	0.60007	1e-05
927	1e+12	NDD	0.60055	0.60028	-0.00027
967	5e+12	NDD	0.60041	0.59915	-0.00126
1204	1e+13	NDD	0.60039	0.59798	-0.00241
1284	1e+13	NDD	0.60001	0.5977	-0.00231
1292	5e+12	NDD	0.60065	0.5995	-0.00115
1364	1e+13	NDD	0.6006	0.59801	-0.00259
1383	5e+12	NDD	0.60064	0.59957	-0.00107
1388	5e+12	NDD	0.60056	0.59936	-0.0012
1427	1e+13	NDD	0.60048	0.59824	-0.00224
1666	0	CORRELATION	0.60058	0.60055	-3e-05

Test Statistics (V)

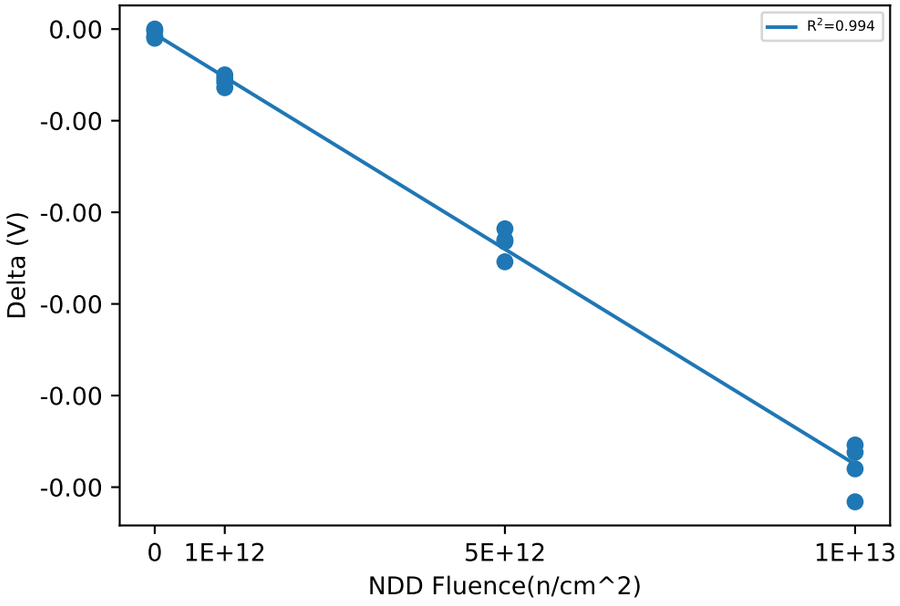
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59995	0.60026	0.60058	0.00030254	0.59994	0.60024	0.60055	0.0002832	-5e-05	-2e-05	1e-05	2.582e-05
1e+12	0.60011	0.60042	0.60062	0.00022589	0.59987	0.60015	0.60032	0.00020419	-0.0003	-0.000275	-0.00024	2.6458e-05
5e+12	0.60041	0.60057	0.60065	0.00011091	0.59915	0.5994	0.59957	0.0001852	-0.00126	-0.00117	-0.00107	8.0416e-05
1e+13	0.60001	0.60037	0.6006	0.00025495	0.5977	0.59798	0.59824	0.00022127	-0.00259	-0.0023875	-0.00224	0.00015196

Device Test: 19.77 VOLTAGE|VREF//4.5/4.5/0/1000/4.5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

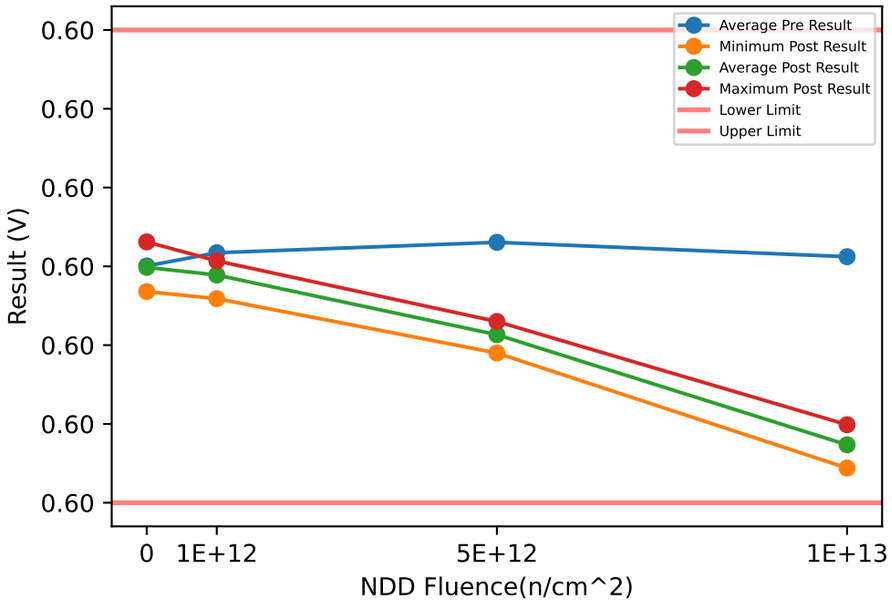
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60018	0.60013	-5e-05
466	1e+12	NDD	0.60014	0.59985	-0.00029
762	0	CORRELATION	0.59968	0.59967	-1e-05
769	1e+12	NDD	0.59982	0.59957	-0.00025
887	1e+12	NDD	0.60037	0.60005	-0.00032
891	0	CORRELATION	0.59979	0.59979	0
927	1e+12	NDD	0.60031	0.60004	-0.00027
967	5e+12	NDD	0.60016	0.59889	-0.00127
1204	1e+13	NDD	0.60011	0.59771	-0.0024
1284	1e+13	NDD	0.59974	0.59743	-0.00231
1292	5e+12	NDD	0.60037	0.59922	-0.00115
1364	1e+13	NDD	0.60035	0.59777	-0.00258
1383	5e+12	NDD	0.60037	0.59928	-0.00109
1388	5e+12	NDD	0.60024	0.59908	-0.00116
1427	1e+13	NDD	0.60024	0.59797	-0.00227
1666	0	CORRELATION	0.60035	0.60031	-4e-05

Test Statistics (V)

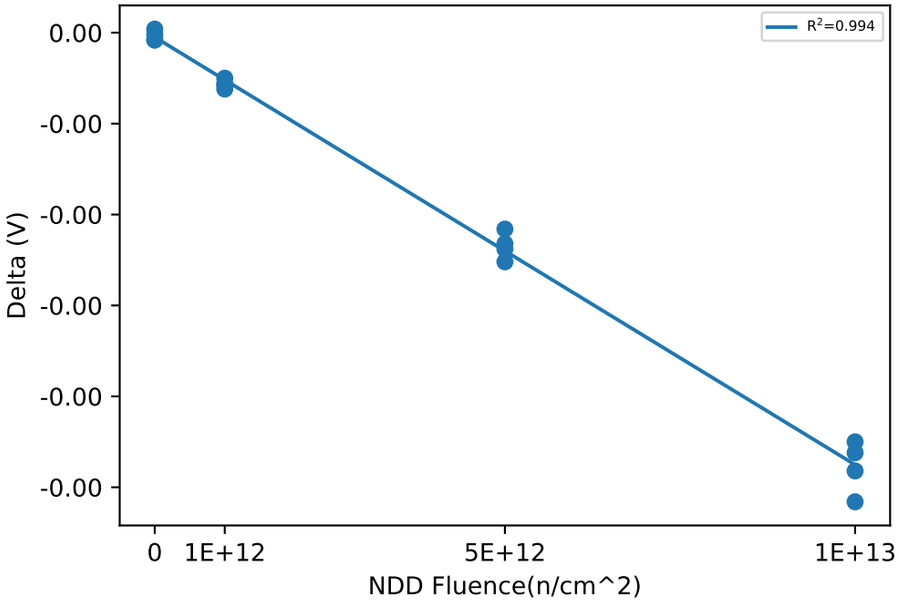
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59968	0.6	0.60035	0.00031696	0.59967	0.59998	0.60031	0.00029637	-5e-05	-2.5e-05	0	2.3805e-05
1e+12	0.59982	0.60016	0.60037	0.00024671	0.59957	0.59988	0.60005	0.0002247	-0.00032	-0.0002825	-0.00025	2.9861e-05
5e+12	0.60016	0.60028	0.60037	0.00010344	0.59889	0.59912	0.59928	0.00017328	-0.00127	-0.0011675	-0.00109	7.5e-05
1e+13	0.59974	0.60011	0.60035	0.00026546	0.59743	0.59772	0.59797	0.00022301	-0.00258	-0.00239	-0.00227	0.00013784

Device Test: 19.79 VOLTAGE|VREF//5/5/0/1000/5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



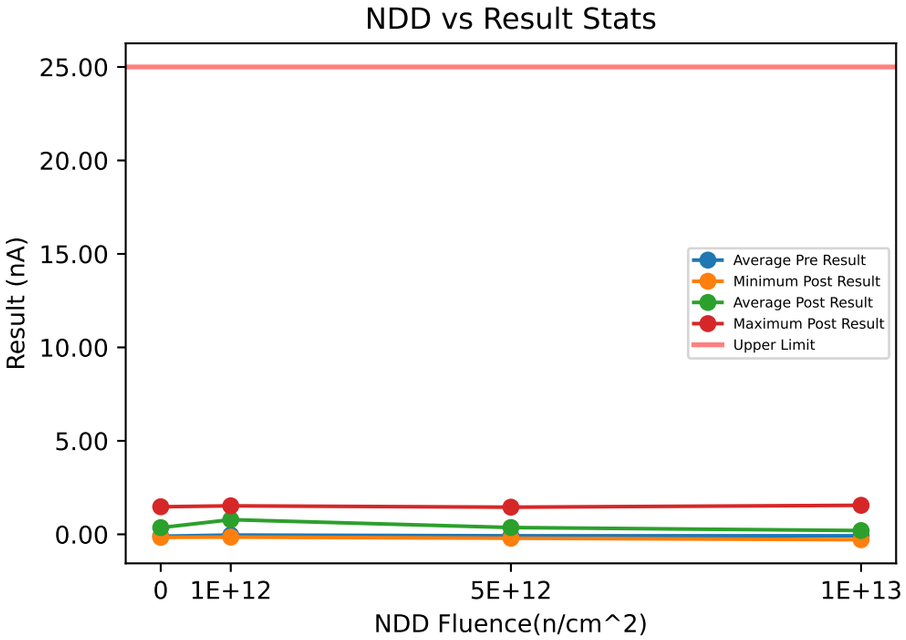
Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

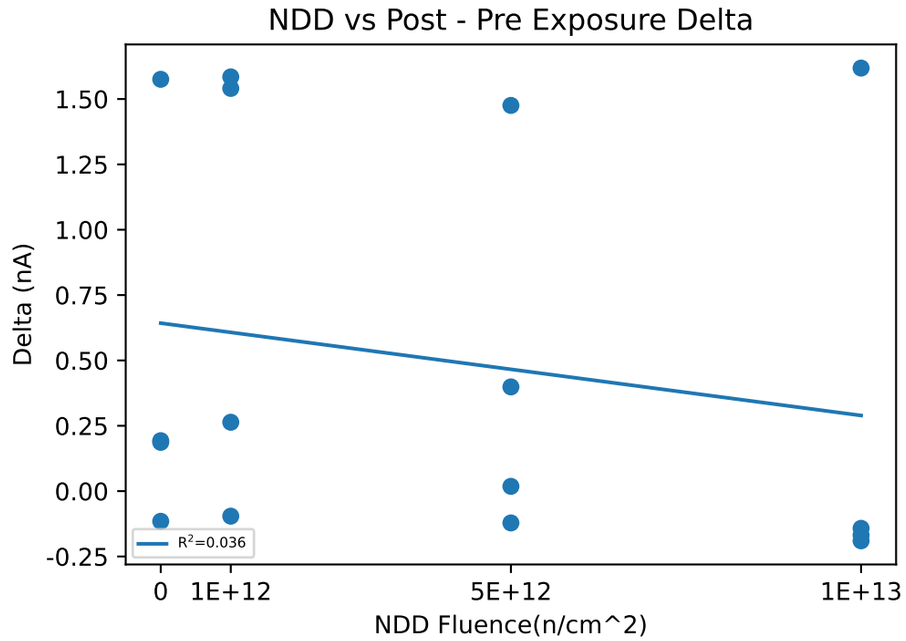
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6002	0.60016	-4e-05
466	1e+12	NDD	0.60015	0.59986	-0.00029
762	0	CORRELATION	0.59969	0.59968	-1e-05
769	1e+12	NDD	0.59984	0.59959	-0.00025
887	1e+12	NDD	0.60038	0.60007	-0.00031
891	0	CORRELATION	0.59978	0.5998	2e-05
927	1e+12	NDD	0.60032	0.60004	-0.00028
967	5e+12	NDD	0.60016	0.5989	-0.00126
1204	1e+13	NDD	0.60013	0.59772	-0.00241
1284	1e+13	NDD	0.59975	0.59744	-0.00231
1292	5e+12	NDD	0.6004	0.59924	-0.00116
1364	1e+13	NDD	0.60037	0.59779	-0.00258
1383	5e+12	NDD	0.60038	0.5993	-0.00108
1388	5e+12	NDD	0.60028	0.59909	-0.00119
1427	1e+13	NDD	0.60024	0.59799	-0.00225
1666	0	CORRELATION	0.60035	0.60031	-4e-05

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.59969	0.60001	0.60035	0.00031984	0.59968	0.59999	0.60031	0.00029635	-4e-05	-1.75e-05	2e-05	2.8723e-05
1e+12	0.59984	0.60017	0.60038	0.00024213	0.59959	0.59989	0.60007	0.00022045	-0.00031	-0.0002825	-0.00025	2.5e-05
5e+12	0.60016	0.60031	0.6004	0.00011	0.5989	0.59913	0.5993	0.0001784	-0.00126	-0.0011725	-0.00108	7.4554e-05
1e+13	0.59975	0.60012	0.60037	0.000267	0.59744	0.59774	0.59799	0.00022752	-0.00258	-0.0023875	-0.00225	0.00014431

Device Test: 19.8 CURRENT|EA//5/5/0/0/5/500kHz//@EA_IB





Test Results (Upper Limit = 25.0 (nA))

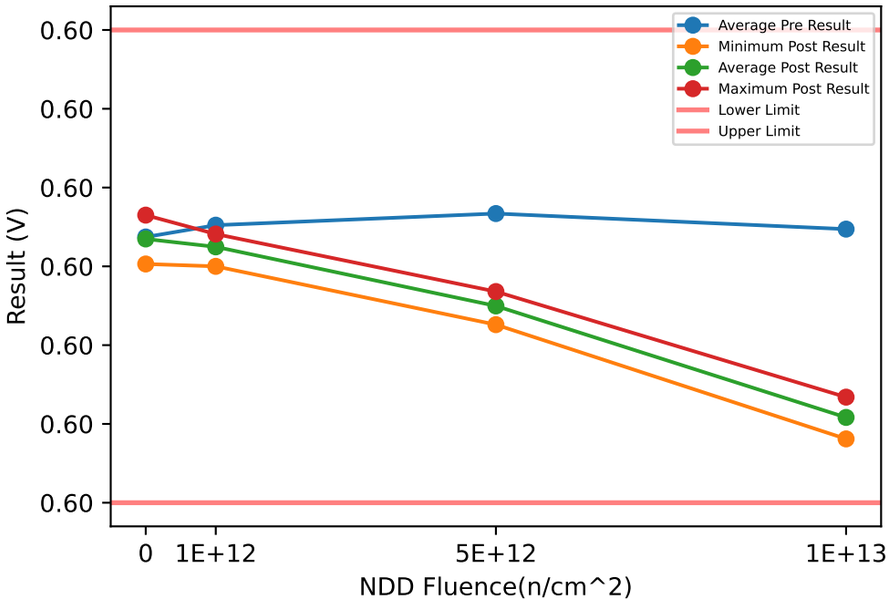
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	-0.0633	0.1297	0.193
466	1e+12	NDD	-0.0476	1.493	1.5406
762	0	CORRELATION	-0.1941	-0.0075	0.1866
769	1e+12	NDD	-0.0605	1.5242	1.5847
887	1e+12	NDD	-0.0536	-0.1494	-0.0958
891	0	CORRELATION	-0.0465	-0.1619	-0.1154
927	1e+12	NDD	0.0066	0.2701	0.2635
967	5e+12	NDD	-0.023	1.4525	1.4755
1204	1e+13	NDD	-0.0777	-0.2462	-0.1685
1284	1e+13	NDD	-0.0695	-0.2118	-0.1423
1292	5e+12	NDD	-0.087	-0.2087	-0.1217
1364	1e+13	NDD	-0.098	-0.2881	-0.1901
1383	5e+12	NDD	-0.1941	0.2046	0.3987
1388	5e+12	NDD	-0.0102	0.0081	0.0183
1427	1e+13	NDD	-0.0661	1.5523	1.6184
1666	0	CORRELATION	-0.1011	1.4743	1.5754

Test Statistics (nA)

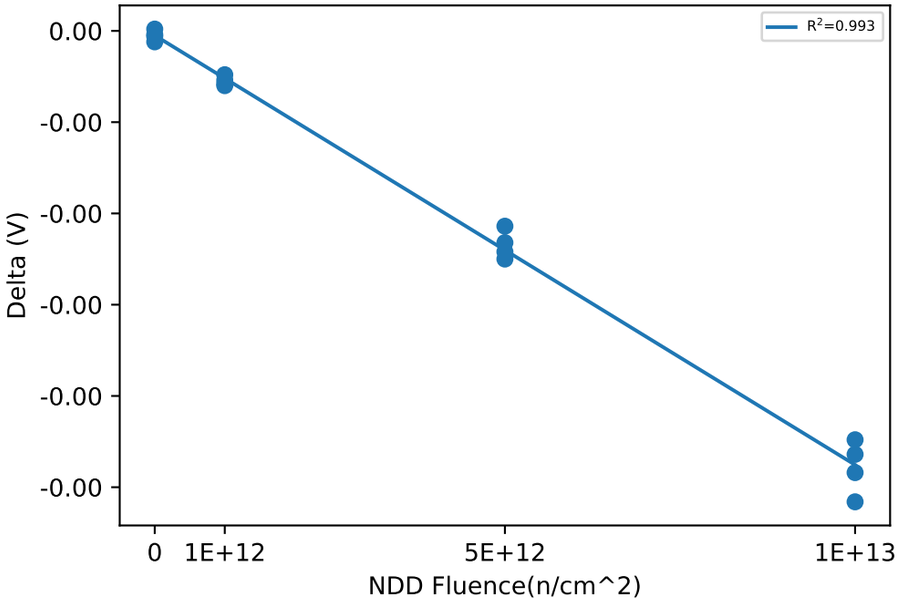
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	-0.1941	-0.10125	-0.0465	0.065977	-0.1619	0.35865	1.4743	0.75324	-0.1154	0.4599	1.5754	0.75746
1e+12	-0.0605	-0.038775	0.0066	0.030706	-0.1494	0.78448	1.5242	0.8536	-0.0958	0.82325	1.5847	0.86648
5e+12	-0.1941	-0.078575	-0.0102	0.084025	-0.2087	0.36412	1.4525	0.74496	-0.1217	0.4427	1.4755	0.72279
1e+13	-0.098	-0.077825	-0.0661	0.014304	-0.2881	0.20155	1.5523	0.90104	-0.1901	0.27938	1.6184	0.8929

Device Test: 19.81 VOLTAGE|VREF//12/12/0/1000/5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

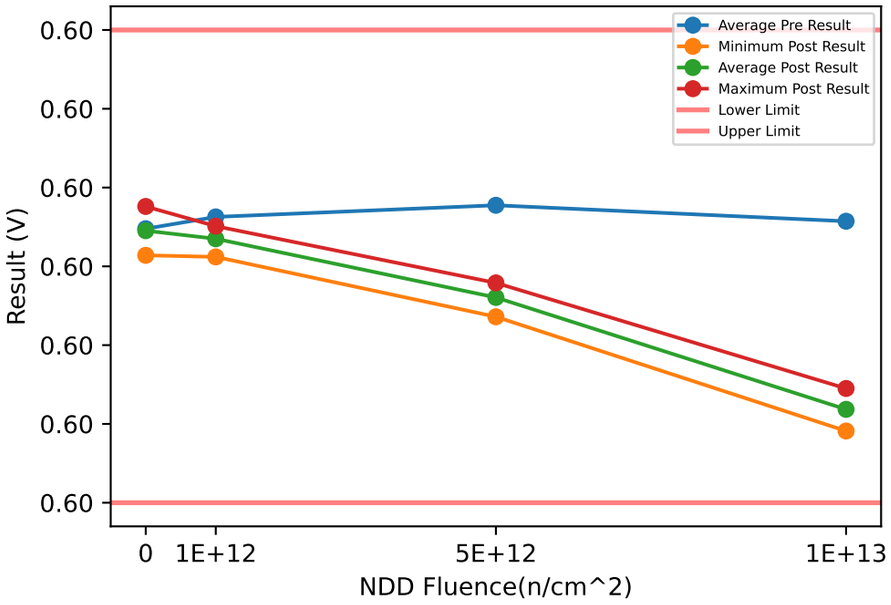
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60057	0.60051	-6e-05
466	1e+12	NDD	0.60049	0.60022	-0.00027
762	0	CORRELATION	0.60005	0.60003	-2e-05
769	1e+12	NDD	0.60024	0.6	-0.00024
887	1e+12	NDD	0.60071	0.60041	-0.0003
891	0	CORRELATION	0.60019	0.6002	1e-05
927	1e+12	NDD	0.60065	0.60036	-0.00029
967	5e+12	NDD	0.60051	0.59926	-0.00125
1204	1e+13	NDD	0.6005	0.59808	-0.00242
1284	1e+13	NDD	0.60013	0.59781	-0.00232
1292	5e+12	NDD	0.60074	0.59958	-0.00116
1364	1e+13	NDD	0.60068	0.5981	-0.00258
1383	5e+12	NDD	0.60075	0.59968	-0.00107
1388	5e+12	NDD	0.60068	0.59947	-0.00121
1427	1e+13	NDD	0.60058	0.59834	-0.00224
1666	0	CORRELATION	0.60068	0.60065	-3e-05

Test Statistics (V)

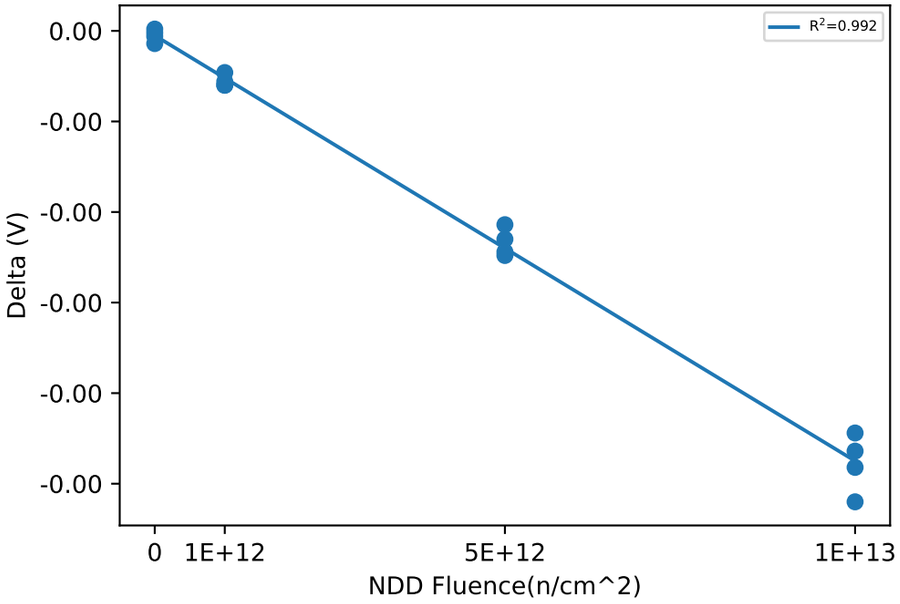
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60005	0.60037	0.60068	0.00030049	0.60003	0.60035	0.60065	0.00028312	-6e-05	-2.5e-05	1e-05	2.8868e-05
1e+12	0.60024	0.60052	0.60071	0.00020998	0.6	0.60025	0.60041	0.00018355	-0.0003	-0.000275	-0.00024	2.6458e-05
5e+12	0.60051	0.60067	0.60075	0.00011106	0.59926	0.5995	0.59968	0.00018007	-0.00125	-0.0011725	-0.00107	7.7621e-05
1e+13	0.60013	0.60047	0.60068	0.00023991	0.59781	0.59808	0.59834	0.0002167	-0.00258	-0.00239	-0.00224	0.00014652

Device Test: 19.83 VOLTAGE|VREF//14/14/0/1000/5/1MHz//@VREF_25C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.597, Upper Limit = 0.603 (V))

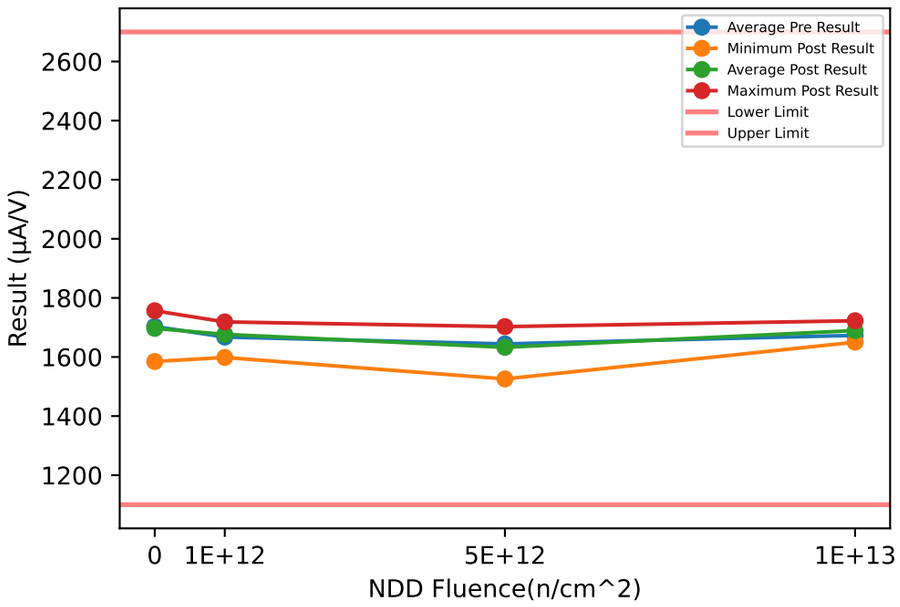
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.60067	0.6006	-7e-05
466	1e+12	NDD	0.6006	0.60032	-0.00028
762	0	CORRELATION	0.60017	0.60014	-3e-05
769	1e+12	NDD	0.60035	0.60012	-0.00023
887	1e+12	NDD	0.60081	0.60051	-0.0003
891	0	CORRELATION	0.6003	0.60031	1e-05
927	1e+12	NDD	0.60075	0.60045	-0.0003
967	5e+12	NDD	0.6006	0.59936	-0.00124
1204	1e+13	NDD	0.60061	0.5982	-0.00241
1284	1e+13	NDD	0.60023	0.59791	-0.00232
1292	5e+12	NDD	0.60084	0.59969	-0.00115
1364	1e+13	NDD	0.60078	0.59818	-0.0026
1383	5e+12	NDD	0.60086	0.59979	-0.00107
1388	5e+12	NDD	0.6008	0.59958	-0.00122
1427	1e+13	NDD	0.60067	0.59845	-0.00222
1666	0	CORRELATION	0.60077	0.60076	-1e-05

Test Statistics (V)

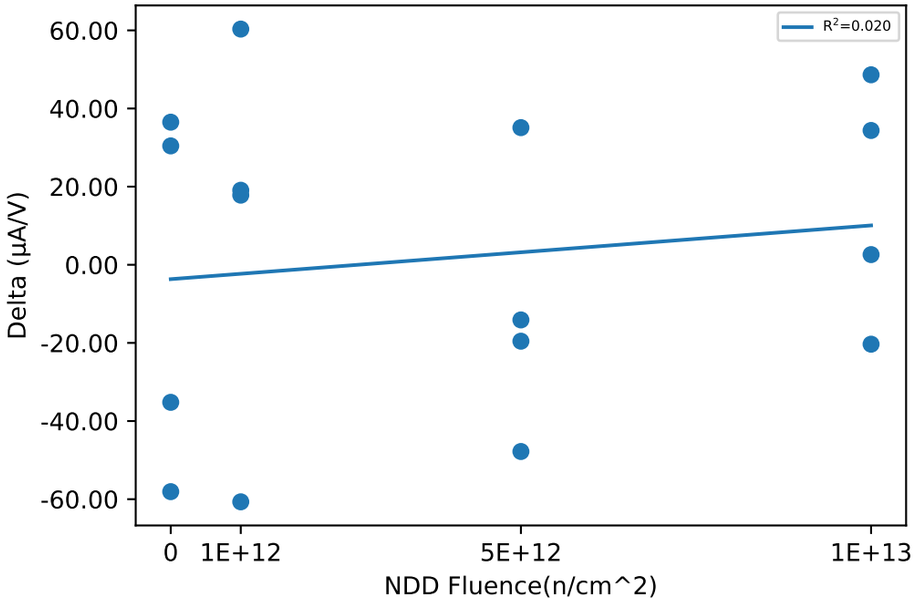
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.60017	0.60048	0.60077	0.00028791	0.60014	0.60045	0.60076	0.00027945	-7e-05	-2.5e-05	1e-05	3.4157e-05
1e+12	0.60035	0.60063	0.60081	0.000205	0.60012	0.60035	0.60051	0.00017263	-0.0003	-0.0002775	-0.00023	3.304e-05
5e+12	0.6006	0.60078	0.60086	0.0001193	0.59936	0.5996	0.59979	0.00018448	-0.00124	-0.00117	-0.00107	7.7028e-05
1e+13	0.60023	0.60057	0.60078	0.00023894	0.59791	0.59818	0.59845	0.00022068	-0.0026	-0.0023875	-0.00222	0.00016153

Device Test: 19.9 LEVEL|TRANSCONDUCTANCE//12/12/0/0/5/500kHz//@EA_GM

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1100.0, Upper Limit = 2700.0 (µA/V))

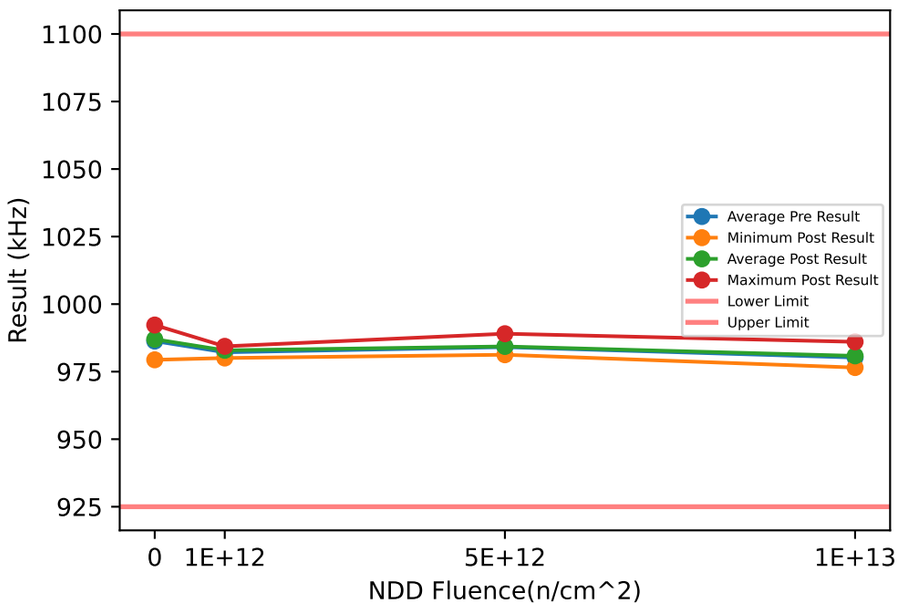
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1799.4	1741.3	-58.073
466	1e+12	NDD	1779.4	1718.7	-60.675
762	0	CORRELATION	1739.5	1704.3	-35.207
769	1e+12	NDD	1538.1	1598.4	60.329
887	1e+12	NDD	1667	1684.8	17.82
891	0	CORRELATION	1554.3	1584.7	30.427
927	1e+12	NDD	1685.2	1704.3	19.079
967	5e+12	NDD	1720	1700.4	-19.559
1204	1e+13	NDD	1650.4	1684.8	34.375
1284	1e+13	NDD	1601.4	1650.1	48.63
1292	5e+12	NDD	1667.6	1702.7	35.102
1364	1e+13	NDD	1720	1722.6	2.6048
1383	5e+12	NDD	1649.8	1602	-47.796
1388	5e+12	NDD	1539.9	1525.7	-14.116
1427	1e+13	NDD	1720.8	1700.4	-20.327
1666	0	CORRELATION	1720	1756.5	36.501

Test Statistics (µA/V)

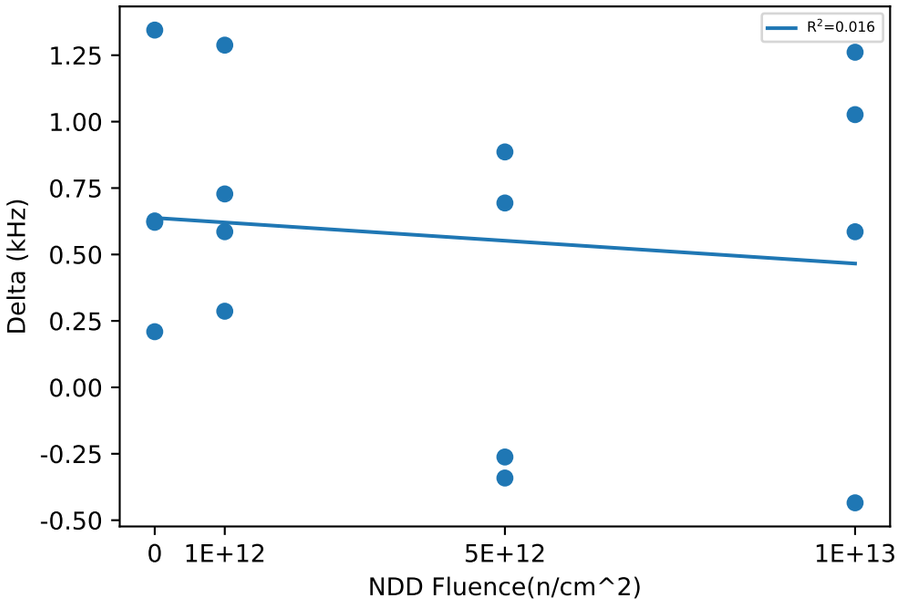
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1554.3	1703.3	1799.4	104.92	1584.7	1696.7	1756.5	77.807	-58.073	-6.588	36.501	47.246
1e+12	1538.1	1667.4	1779.4	99.303	1598.4	1676.6	1718.7	53.917	-60.675	9.1383	60.329	50.559
5e+12	1539.9	1644.3	1720	75.748	1525.7	1632.7	1702.7	85.392	-47.796	-11.592	35.102	34.453
1e+13	1601.4	1673.2	1720.8	58.077	1650.1	1689.5	1722.6	30.503	-20.327	16.321	48.63	31.097

Device Test: 20.101 LEVEL|FREQ/RT/14/14/0/1000/5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

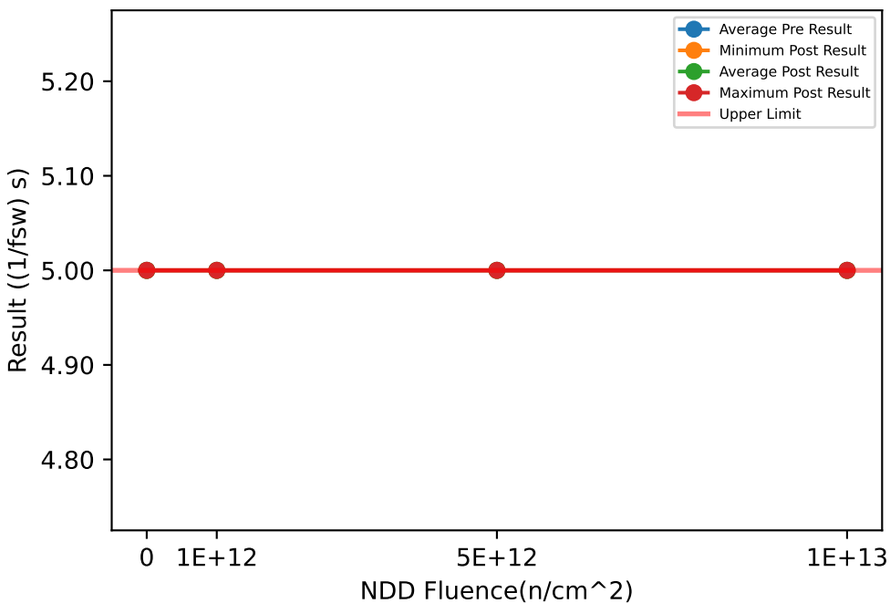
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	987	987.21	0.2094
466	1e+12	NDD	982.14	982.87	0.7279
762	0	CORRELATION	978.76	979.38	0.6263
769	1e+12	NDD	983	984.29	1.2879
887	1e+12	NDD	984.08	984.37	0.2865
891	0	CORRELATION	991.64	992.26	0.6211
927	1e+12	NDD	979.46	980.05	0.5857
967	5e+12	NDD	988.35	989.04	0.6938
1204	1e+13	NDD	984.78	986.04	1.2612
1284	1e+13	NDD	980.18	979.75	-0.4346
1292	5e+12	NDD	981.67	982.55	0.886
1364	1e+13	NDD	975.49	976.52	1.0264
1383	5e+12	NDD	984.73	984.47	-0.2622
1388	5e+12	NDD	981.6	981.26	-0.3413
1427	1e+13	NDD	980.47	981.06	0.5856
1666	0	CORRELATION	987.84	989.18	1.3446

Test Statistics (kHz)

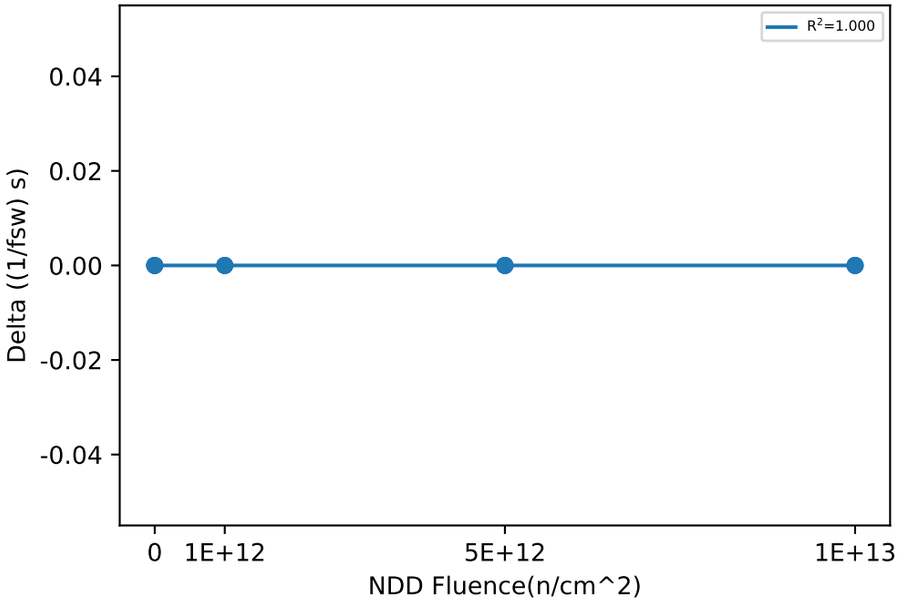
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	978.76	986.31	991.64	5.4247	979.38	987.01	992.26	5.493	0.2094	0.70035	1.3446	0.47182
1e+12	979.46	982.17	984.08	1.9742	980.05	982.89	984.37	2.0192	0.2865	0.722	1.2879	0.41973
5e+12	981.6	984.09	988.35	3.1948	981.26	984.33	989.04	3.4069	-0.3413	0.24408	0.886	0.63595
1e+13	975.49	980.23	984.78	3.7947	976.52	980.84	986.04	3.956	-0.4346	0.60965	1.2612	0.75039

Device Test: 20.112 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/100kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

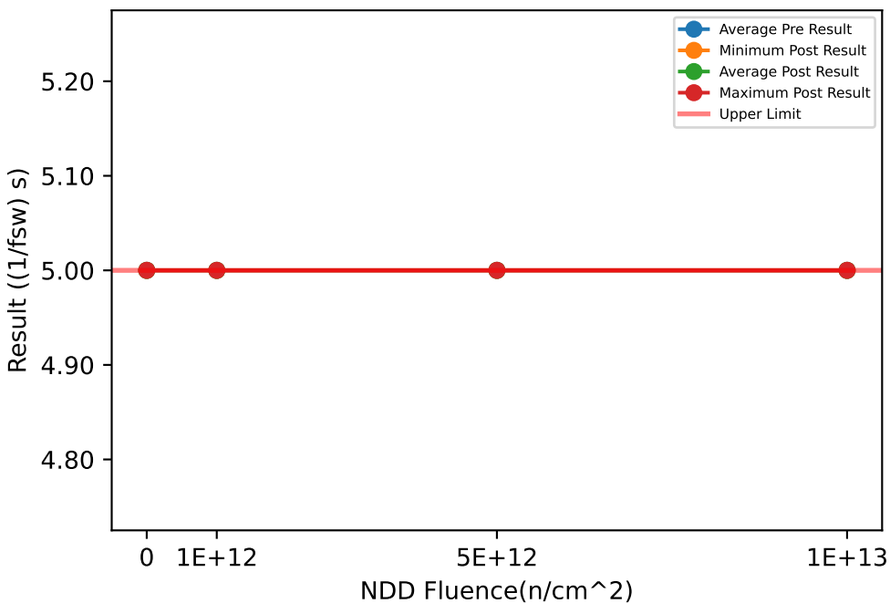
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

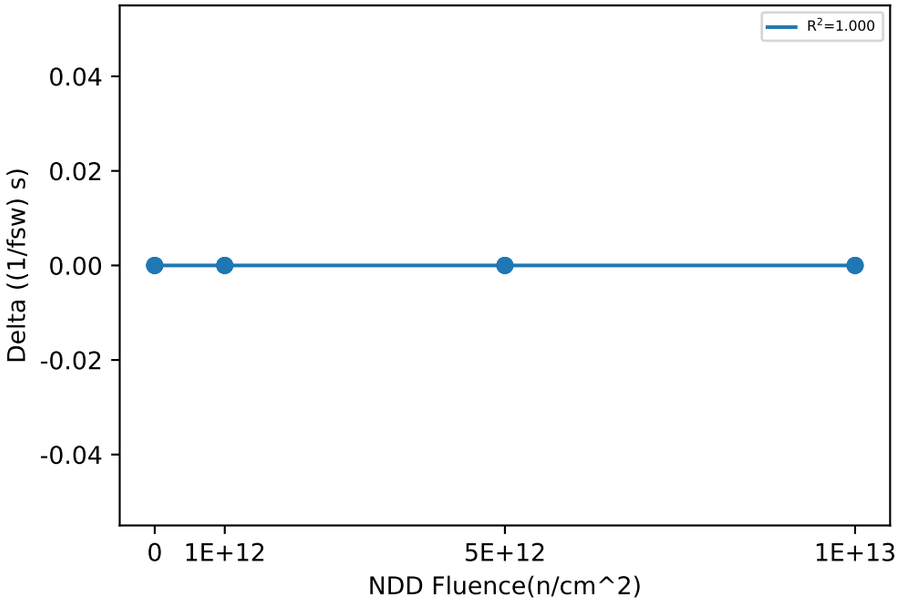
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.114 FREQ|DETECTION/SYNC/5/5/0/0/5/100kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

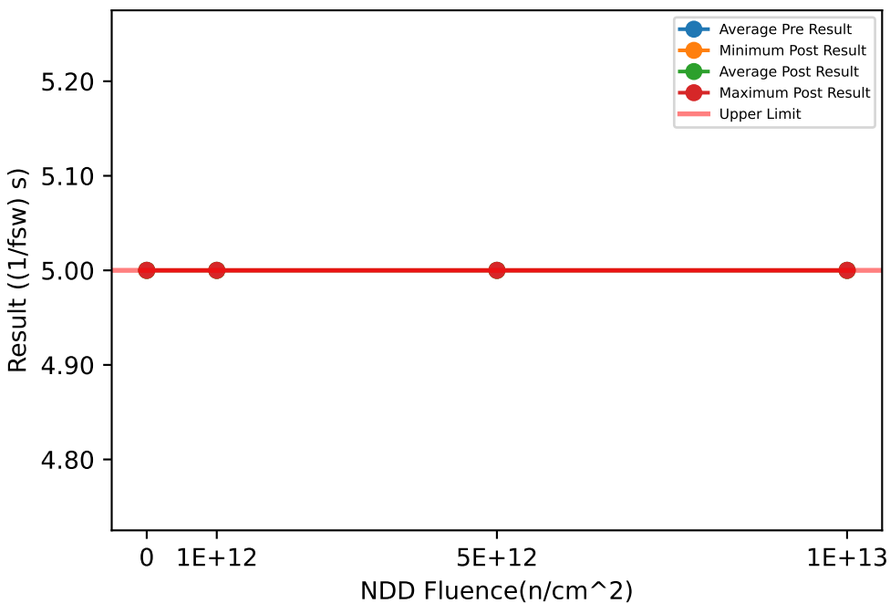
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

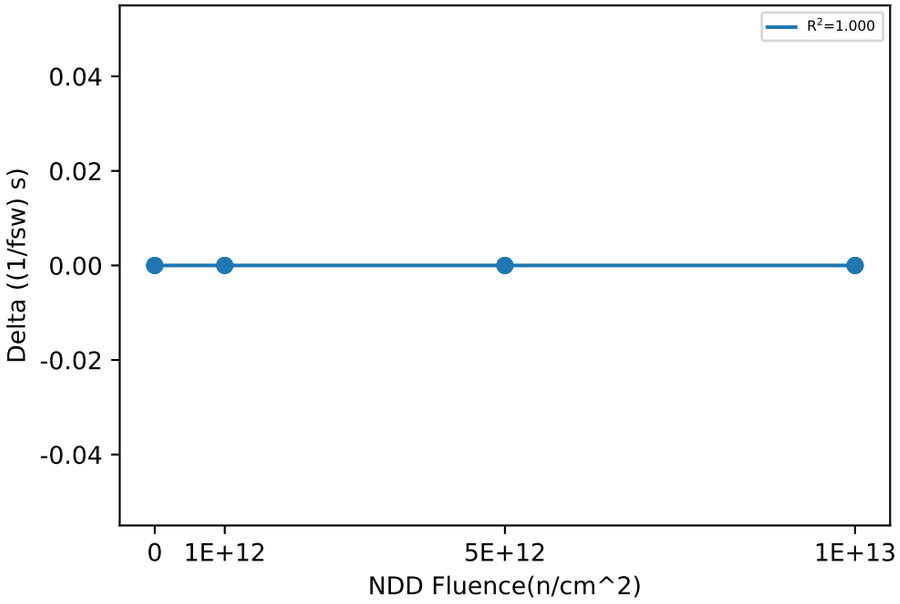
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.116 FREQ|DETECTION/SYNC/12/12/0/0/5/100kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

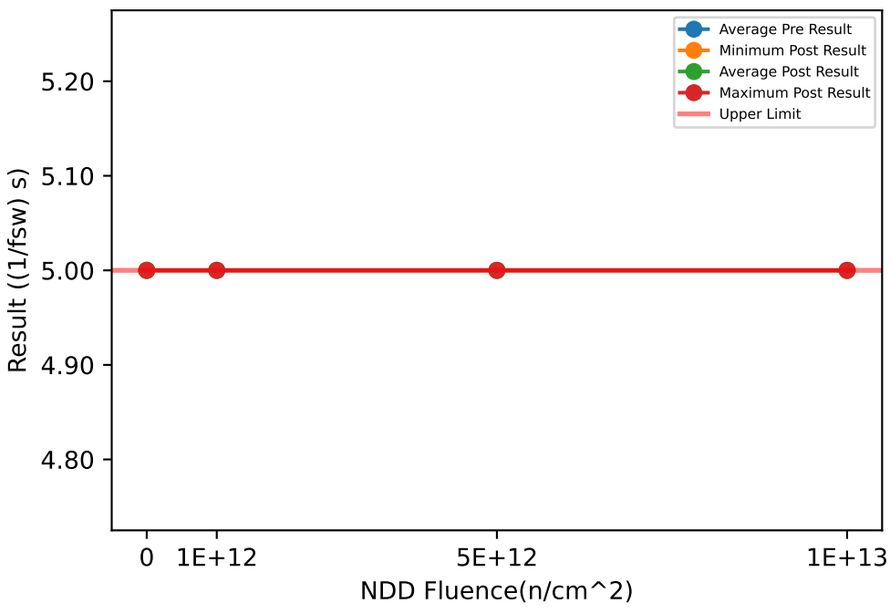
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

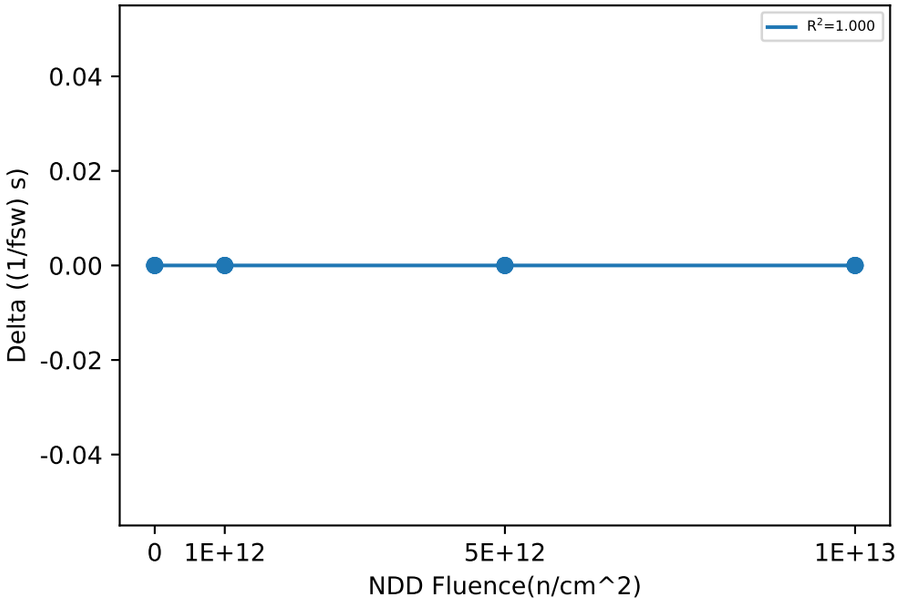
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.118 FREQ|DETECTION/SYNC/14/14/0/0/5/100kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

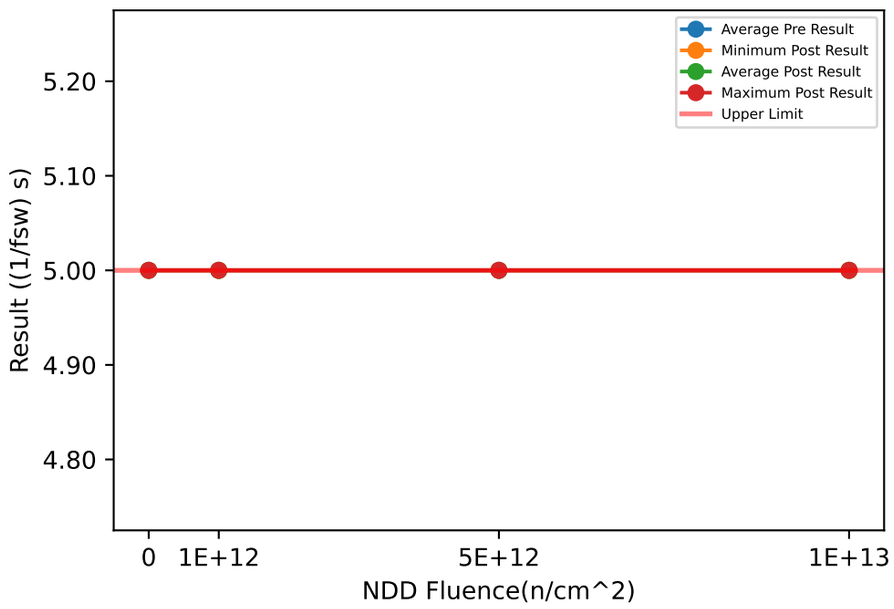
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

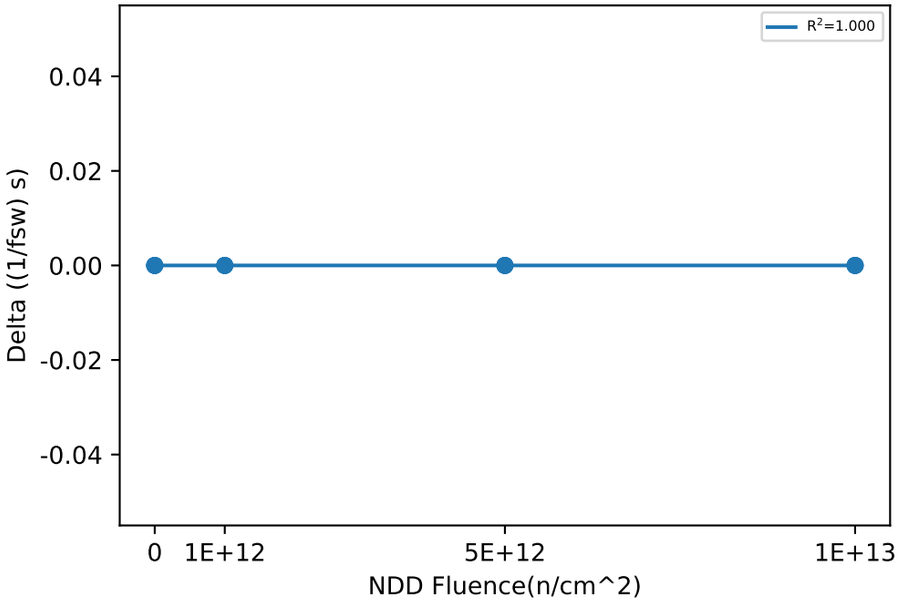
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.120 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/200kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

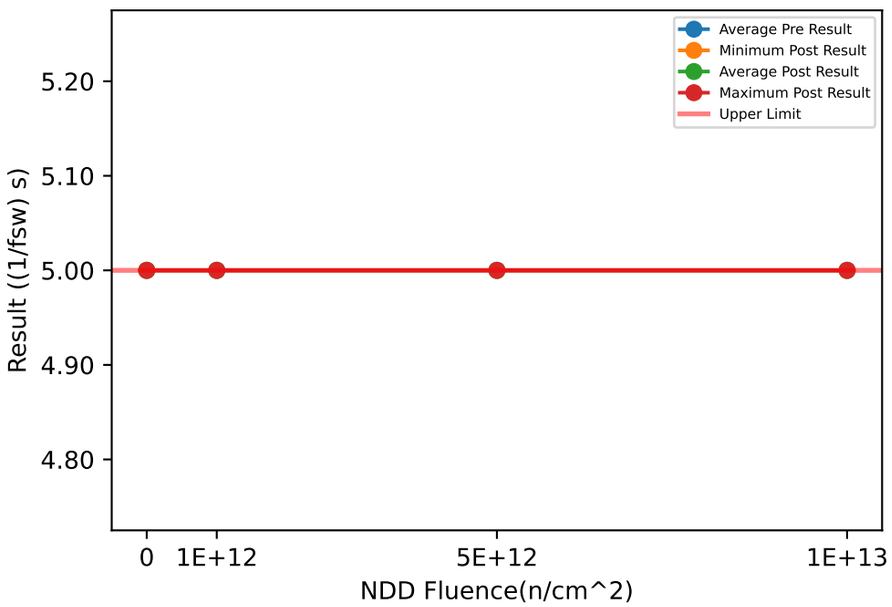
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

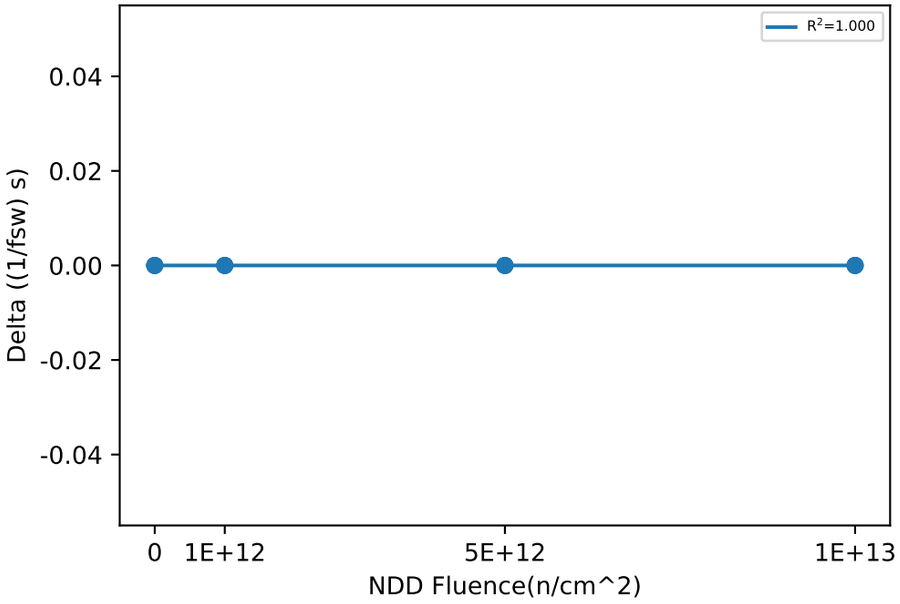
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.122 FREQ|DETECTION/SYNC/5/5/0/0/5/200kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

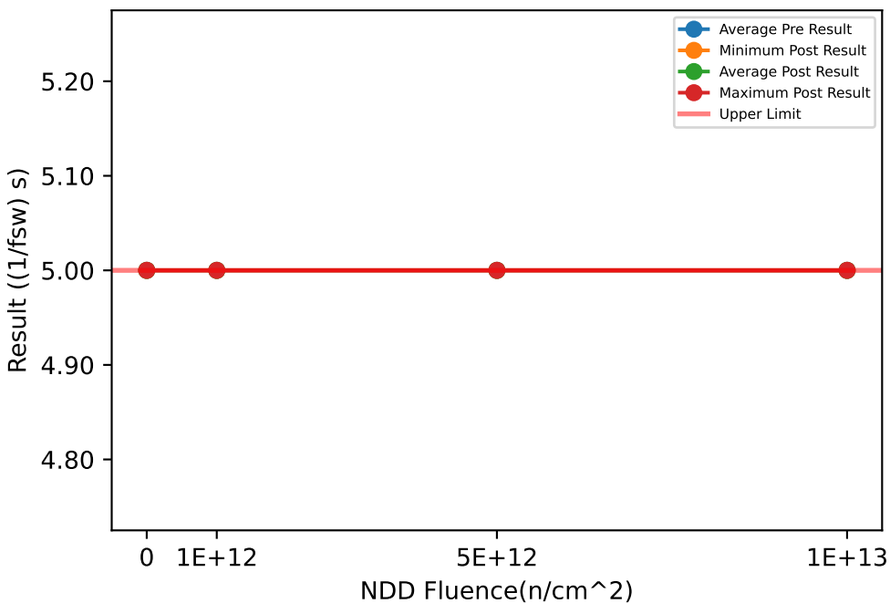
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

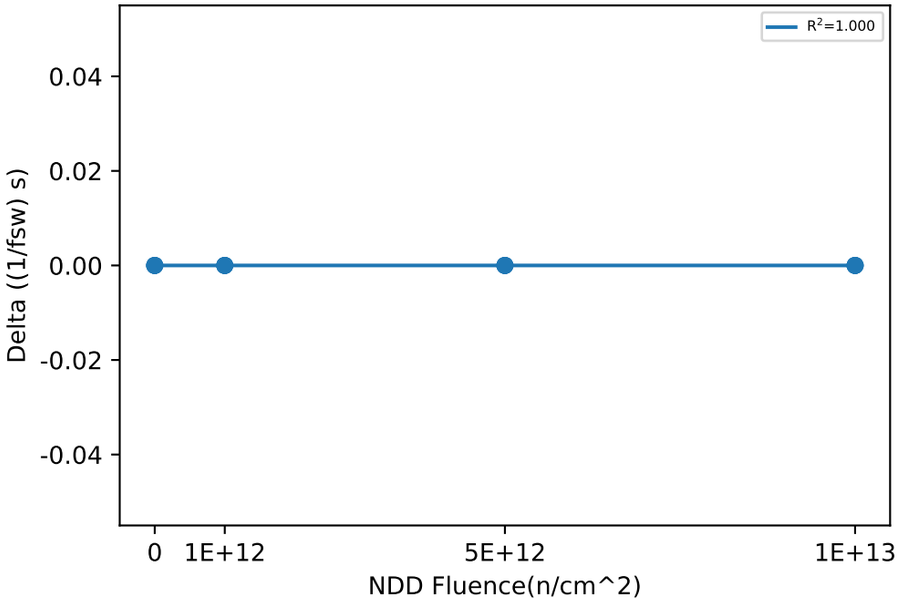
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.124 FREQ|DETECTION/SYNC/12/12/0/0/5/200kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

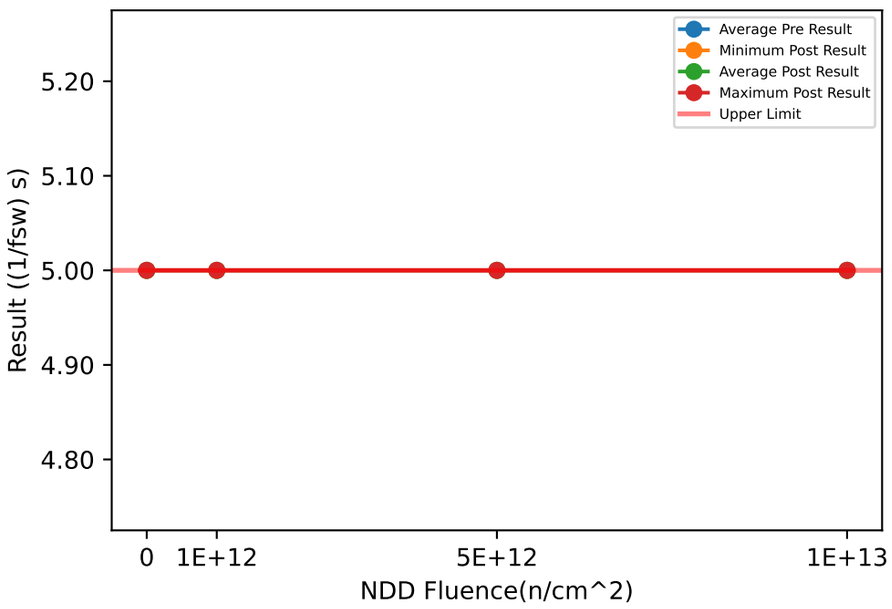
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

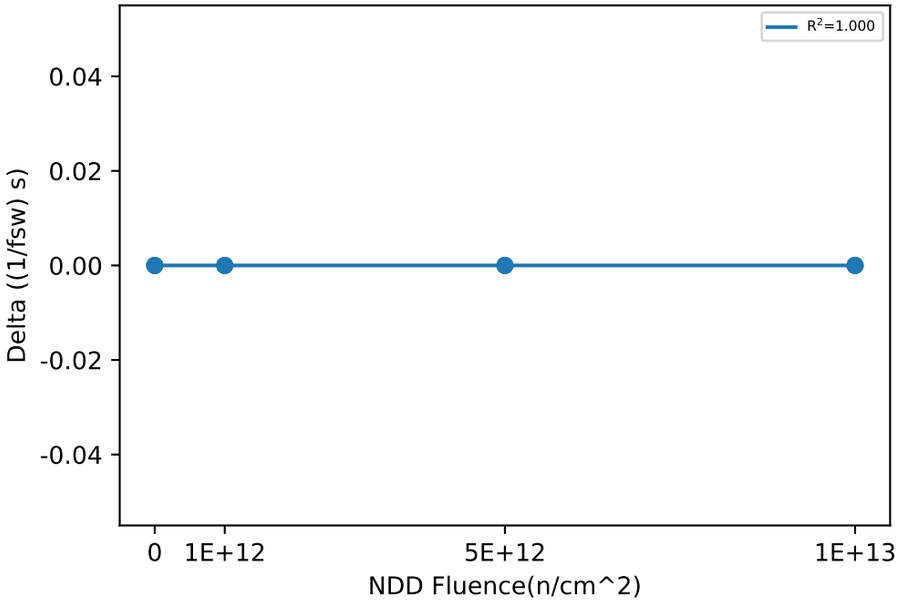
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.126 FREQ|DETECTION/SYNC/14/14/0/0/5/200kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



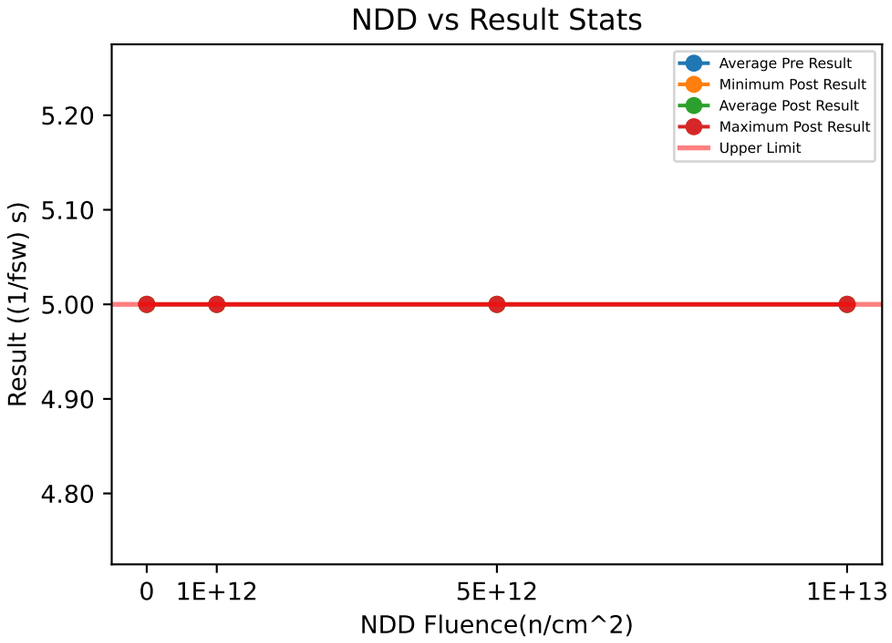
Test Results (Upper Limit = 5.0 ((1/fsw) s))

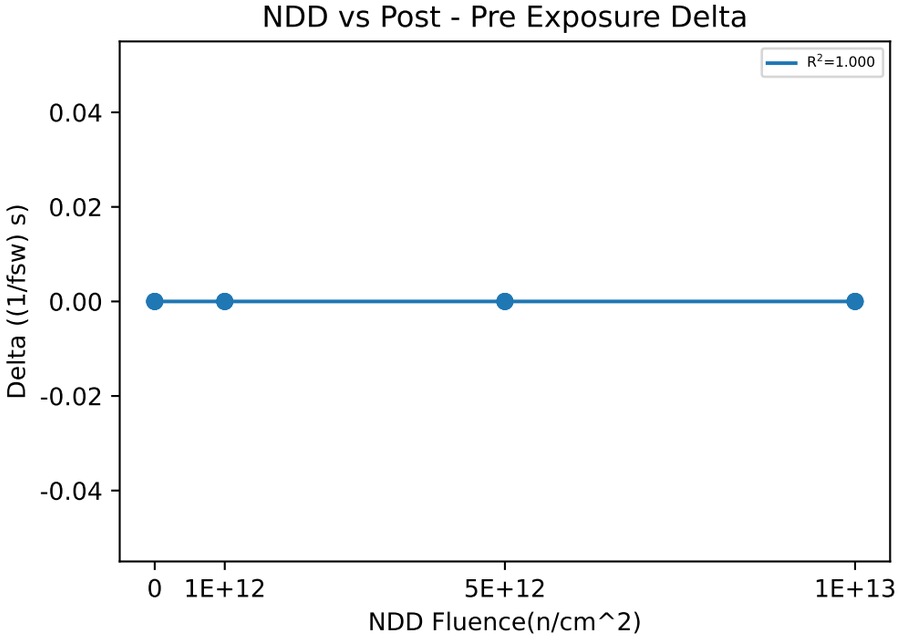
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.128 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/500kHz//@T_SYNC_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

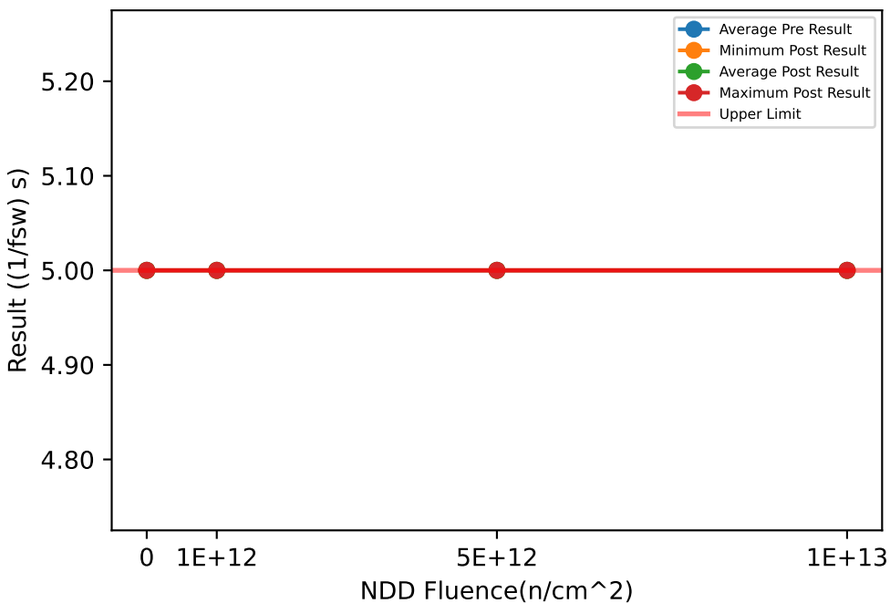
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

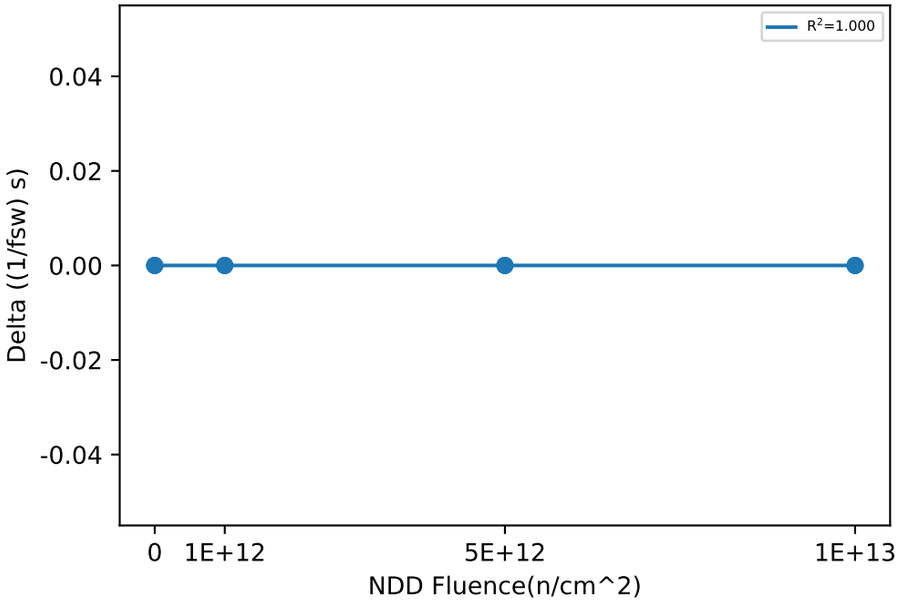
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.130 FREQ|DETECTION/SYNC/5/5/0/0/5/500kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

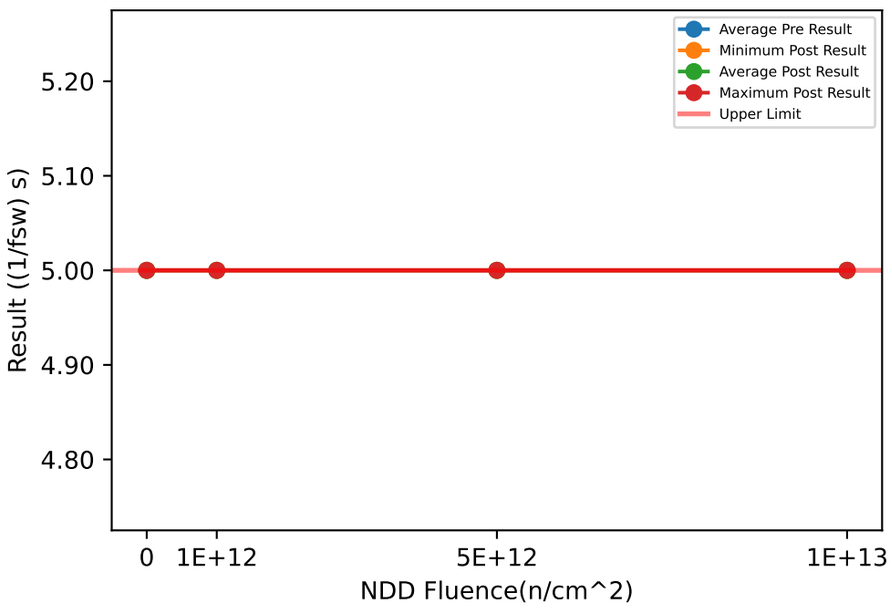
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

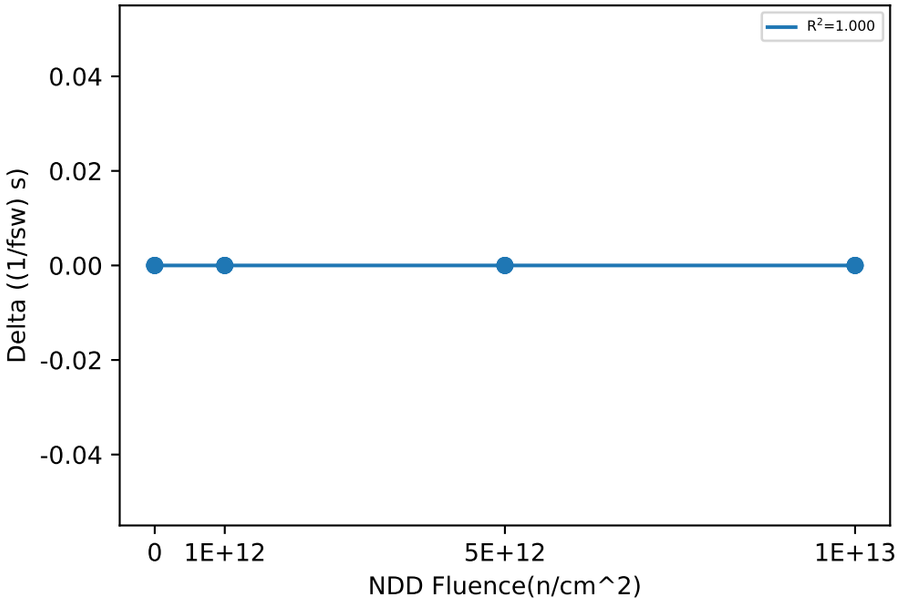
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.132 FREQ|DETECTION/SYNC/12/12/0/0/5/500kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

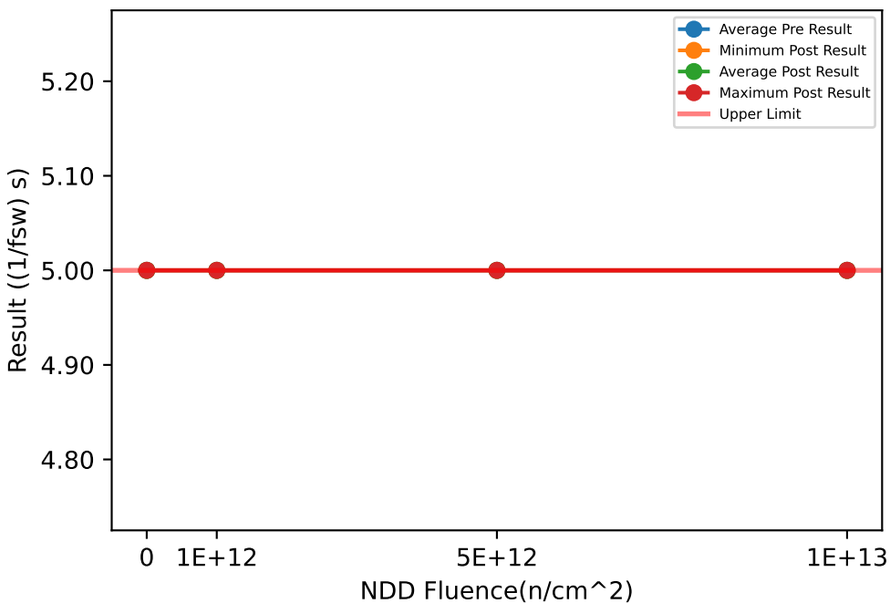
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

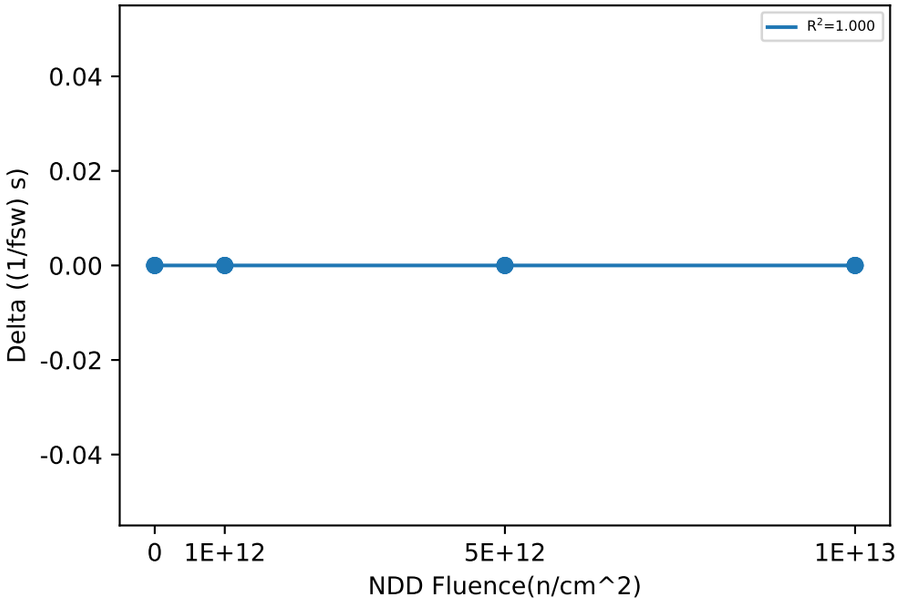
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.134 FREQ|DETECTION/SYNC/14/14/0/0/5/500kHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

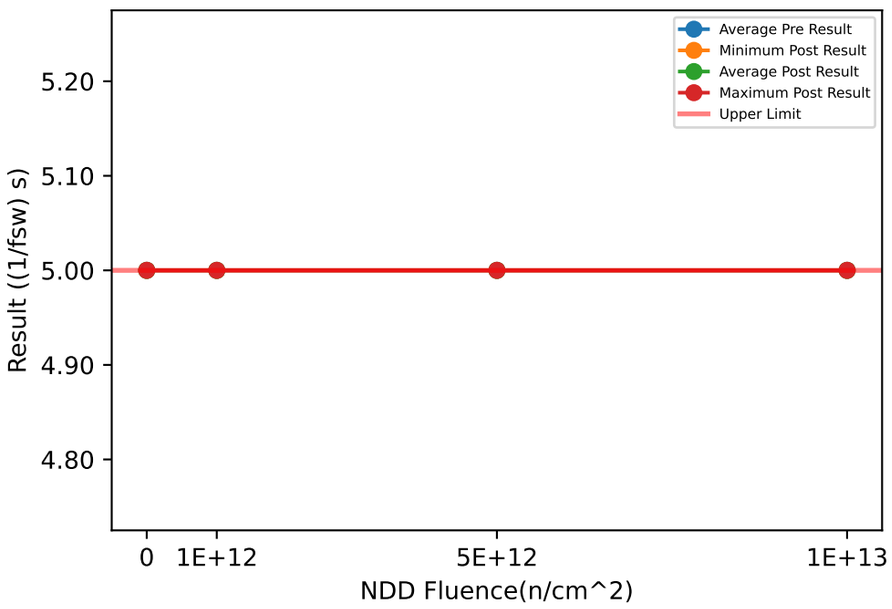
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

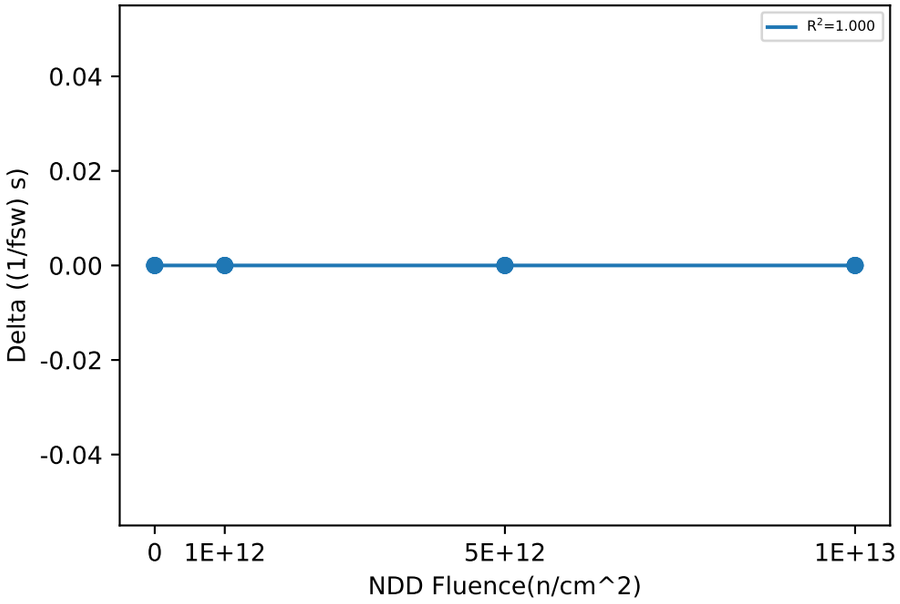
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.136 FREQ|DETECTION/SYNC/4.5/4.5/0/0/4.5/1MHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

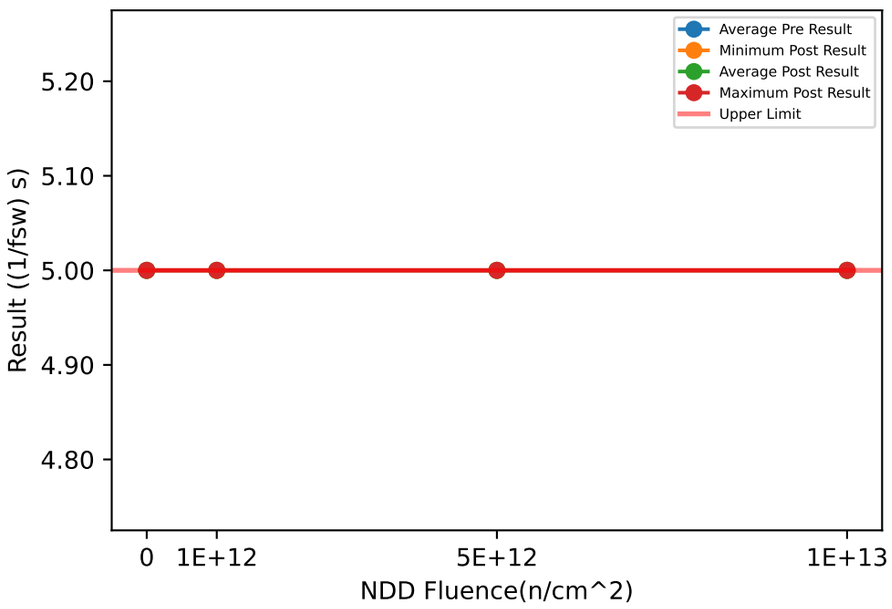
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

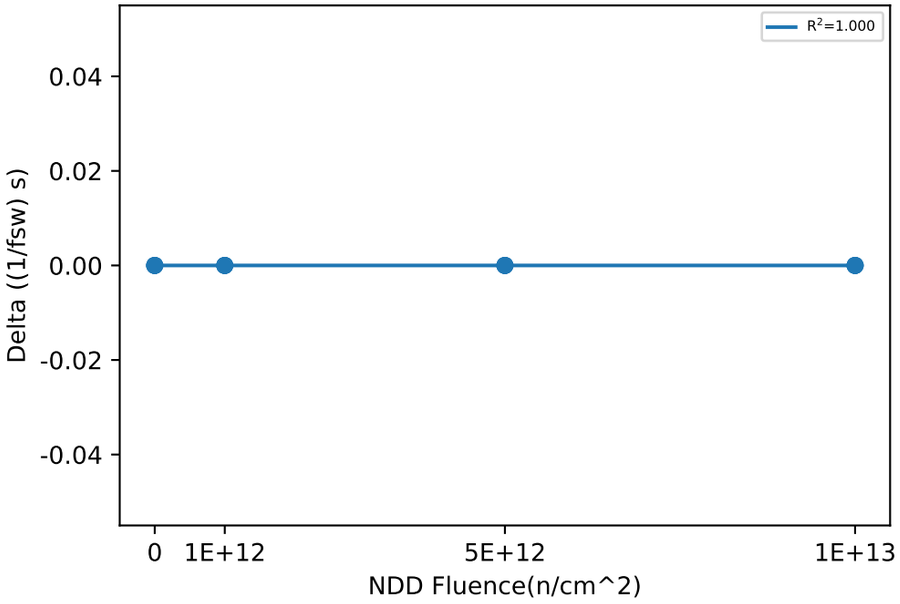
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.138 FREQ|DETECTION/SYNC/5/5/0/0/5/1MHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

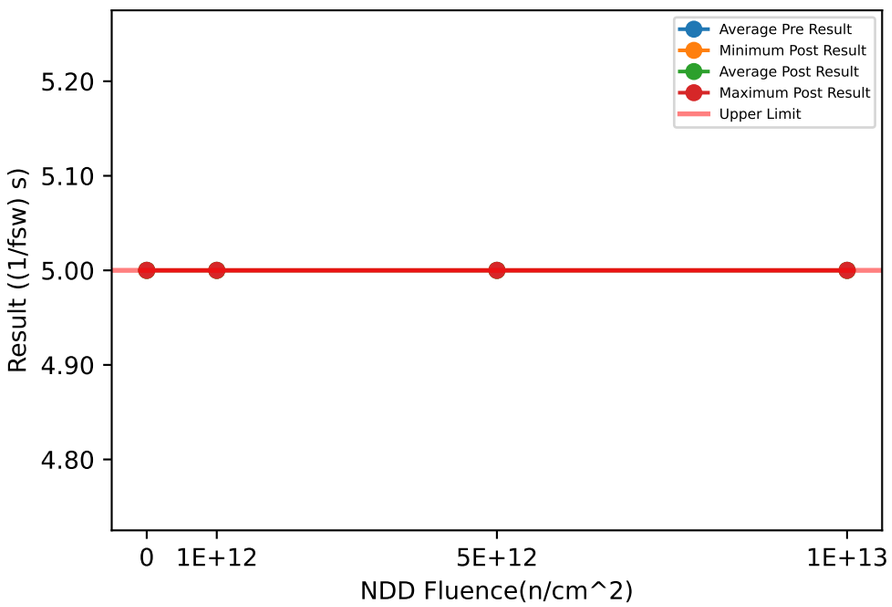
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

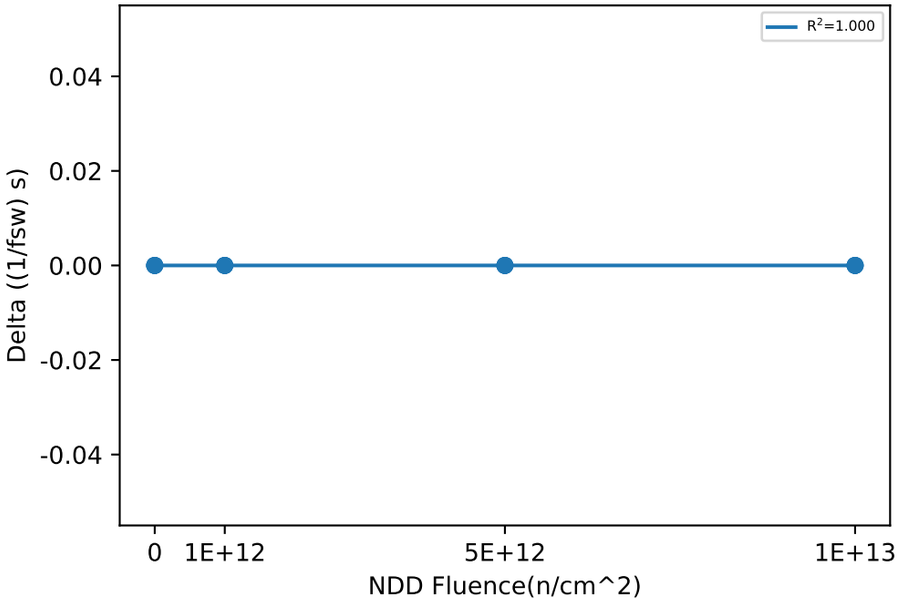
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.140 FREQ|DETECTION/SYNC/12/12/0/0/5/1MHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

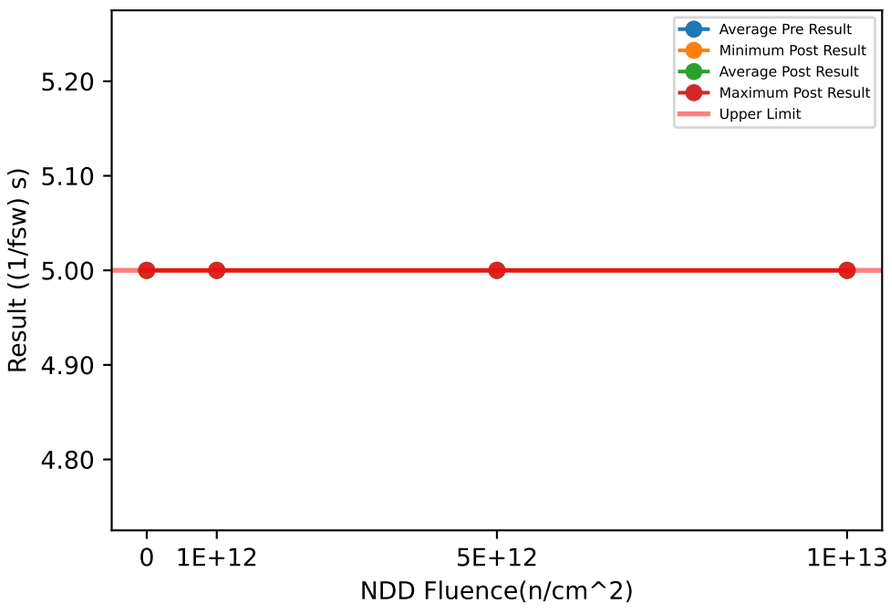
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

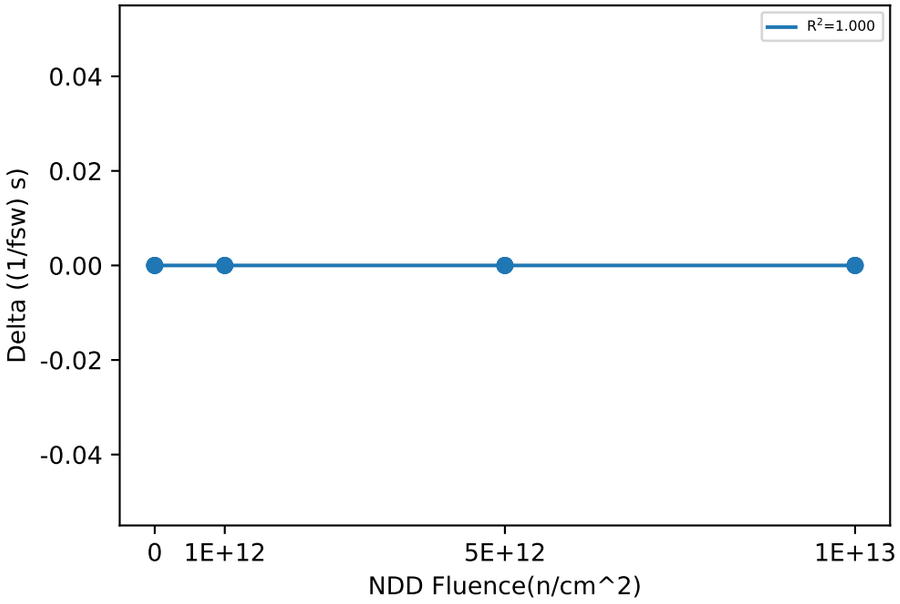
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.142 FREQ|DETECTION/SYNC/14/14/0/0/5/1MHz//@T_SYNC_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

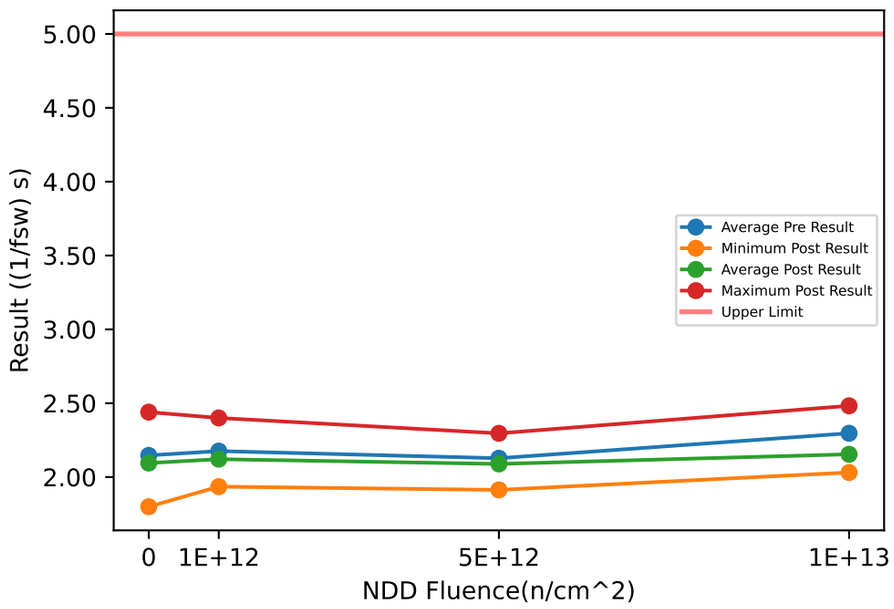
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5	5	0
466	1e+12	NDD	5	5	0
762	0	CORRELATION	5	5	0
769	1e+12	NDD	5	5	0
887	1e+12	NDD	5	5	0
891	0	CORRELATION	5	5	0
927	1e+12	NDD	5	5	0
967	5e+12	NDD	5	5	0
1204	1e+13	NDD	5	5	0
1284	1e+13	NDD	5	5	0
1292	5e+12	NDD	5	5	0
1364	1e+13	NDD	5	5	0
1383	5e+12	NDD	5	5	0
1388	5e+12	NDD	5	5	0
1427	1e+13	NDD	5	5	0
1666	0	CORRELATION	5	5	0

Test Statistics ((1/fsw) s)

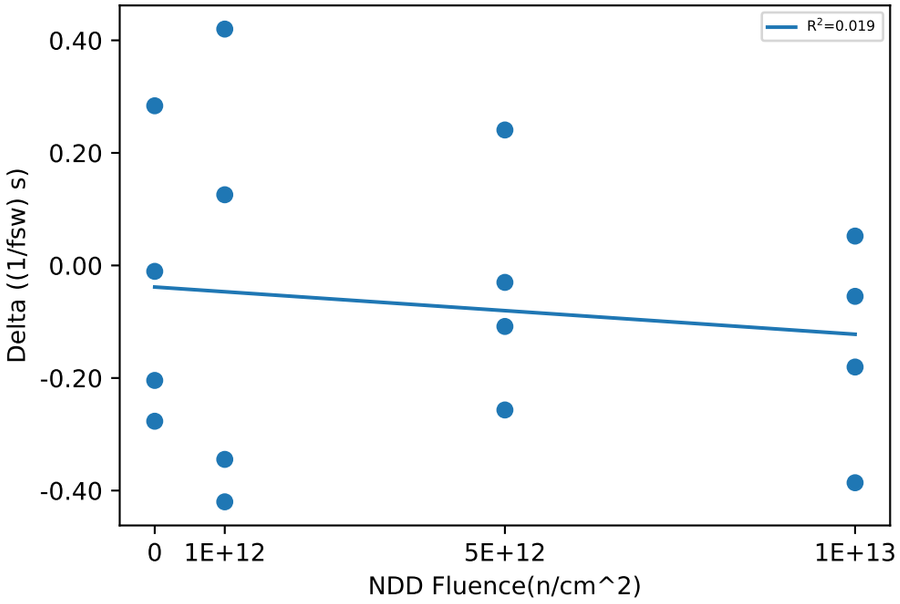
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5	5	5	0	5	5	5	0	0	0	0	0
1e+12	5	5	5	0	5	5	5	0	0	0	0	0
5e+12	5	5	5	0	5	5	5	0	0	0	0	0
1e+13	5	5	5	0	5	5	5	0	0	0	0	0

Device Test: 20.144 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/100kHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

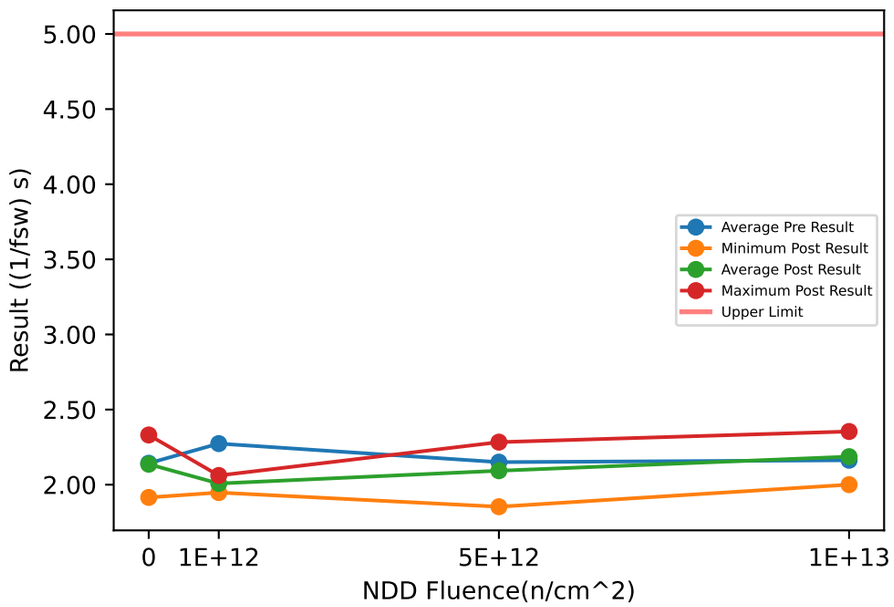
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.1558	2.4395	0.2837
466	1e+12	NDD	1.9995	2.1251	0.1256
762	0	CORRELATION	2.286	2.0817	-0.2043
769	1e+12	NDD	2.3688	2.0242	-0.3446
887	1e+12	NDD	2.355	1.935	-0.42
891	0	CORRELATION	1.8096	1.7991	-0.0105
927	1e+12	NDD	1.9802	2.4002	0.42
967	5e+12	NDD	2.1698	1.913	-0.2568
1204	1e+13	NDD	1.9786	2.0308	0.0522
1284	1e+13	NDD	2.2308	2.0503	-0.1805
1292	5e+12	NDD	2.1202	2.0901	-0.0301
1364	1e+13	NDD	2.5373	2.4824	-0.0549
1383	5e+12	NDD	2.1643	2.0559	-0.1084
1388	5e+12	NDD	2.0554	2.2961	0.2407
1427	1e+13	NDD	2.4386	2.0525	-0.3861
1666	0	CORRELATION	2.3352	2.0584	-0.2768

Test Statistics ((1/fsw) s)

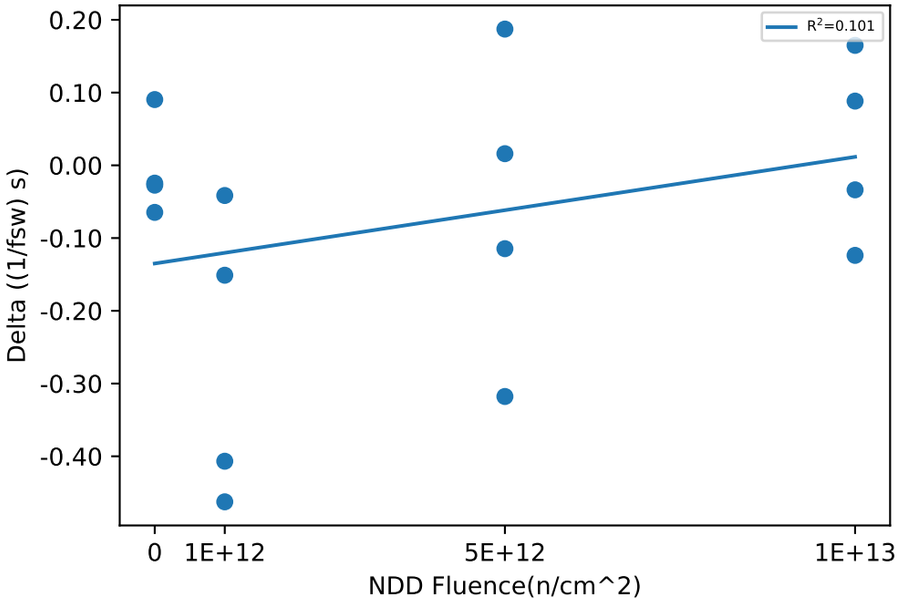
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8096	2.1467	2.3352	0.2371	1.7991	2.0947	2.4395	0.26316	-0.2768	-0.051975	0.2837	0.25043
1e+12	1.9802	2.1759	2.3688	0.21502	1.935	2.1211	2.4002	0.20161	-0.42	-0.05475	0.42	0.39805
5e+12	2.0554	2.1274	2.1698	0.0529	1.913	2.0888	2.2961	0.15807	-0.2568	-0.03865	0.2407	0.20862
1e+13	1.9786	2.2963	2.5373	0.24736	2.0308	2.154	2.4824	0.21915	-0.3861	-0.14232	0.0522	0.1883

Device Test: 20.146 FREQ|DETECTION/RT/5/5/0/0/5/100kHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



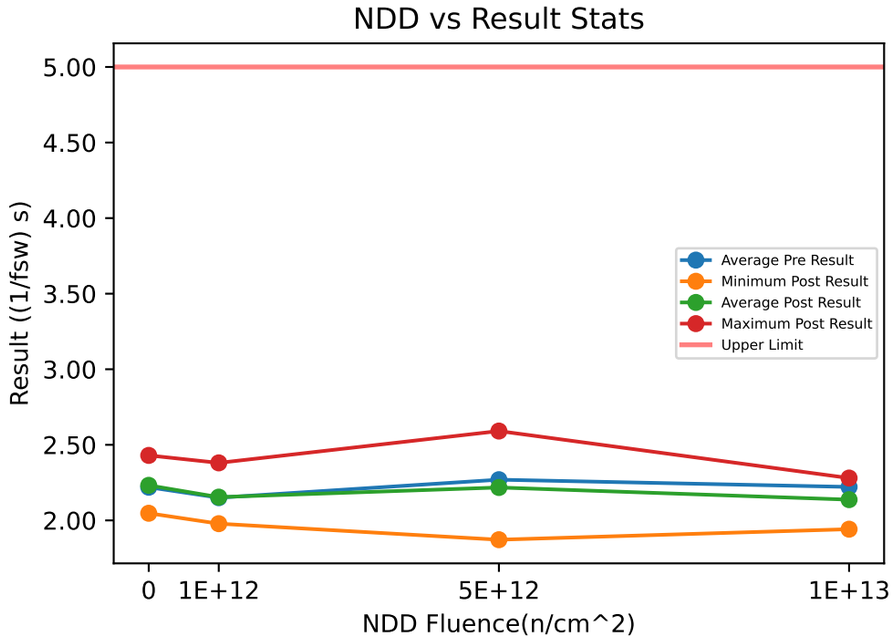
Test Results (Upper Limit = 5.0 ((1/fsw) s))

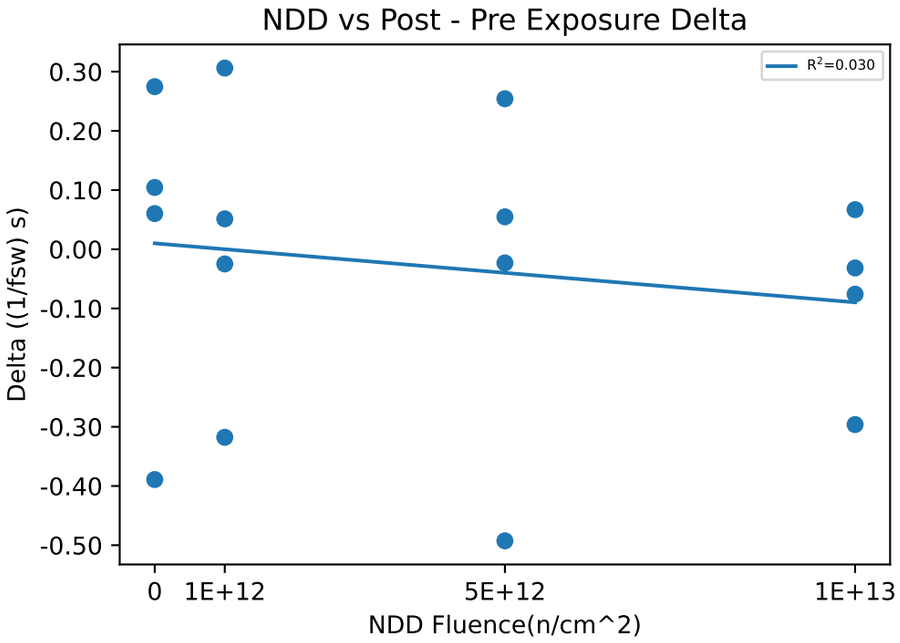
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.0425	2.1329	0.0904
466	1e+12	NDD	2.0763	2.0348	-0.0415
762	0	CORRELATION	2.3957	2.331	-0.0647
769	1e+12	NDD	2.3544	1.9476	-0.4068
887	1e+12	NDD	2.451	1.9884	-0.4626
891	0	CORRELATION	1.9397	1.9152	-0.0245
927	1e+12	NDD	2.2123	2.0612	-0.1511
967	5e+12	NDD	2.1712	1.8534	-0.3178
1204	1e+13	NDD	1.9845	2.1494	0.1649
1284	1e+13	NDD	2.124	2.0002	-0.1238
1292	5e+12	NDD	1.8279	2.0152	0.1873
1364	1e+13	NDD	2.2658	2.3541	0.0883
1383	5e+12	NDD	2.3342	2.2196	-0.1146
1388	5e+12	NDD	2.2673	2.2833	0.016
1427	1e+13	NDD	2.2763	2.2426	-0.0337
1666	0	CORRELATION	2.1933	2.166	-0.0273

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9397	2.1428	2.3957	0.19817	1.9152	2.1363	2.331	0.17096	-0.0647	-0.006525	0.0904	0.067165
1e+12	2.0763	2.2735	2.451	0.164	1.9476	2.008	2.0612	0.050269	-0.4626	-0.2655	-0.0415	0.20172
5e+12	1.8279	2.1502	2.3342	0.22501	1.8534	2.0929	2.2833	0.19639	-0.3178	-0.057275	0.1873	0.21319
1e+13	1.9845	2.1627	2.2763	0.13758	2.0002	2.1866	2.3541	0.1498	-0.1238	0.023925	0.1649	0.12801

Device Test: 20.148 FREQ|DETECTION/RT/12/12/0/0/5/100kHz//@T_INT_CLK_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

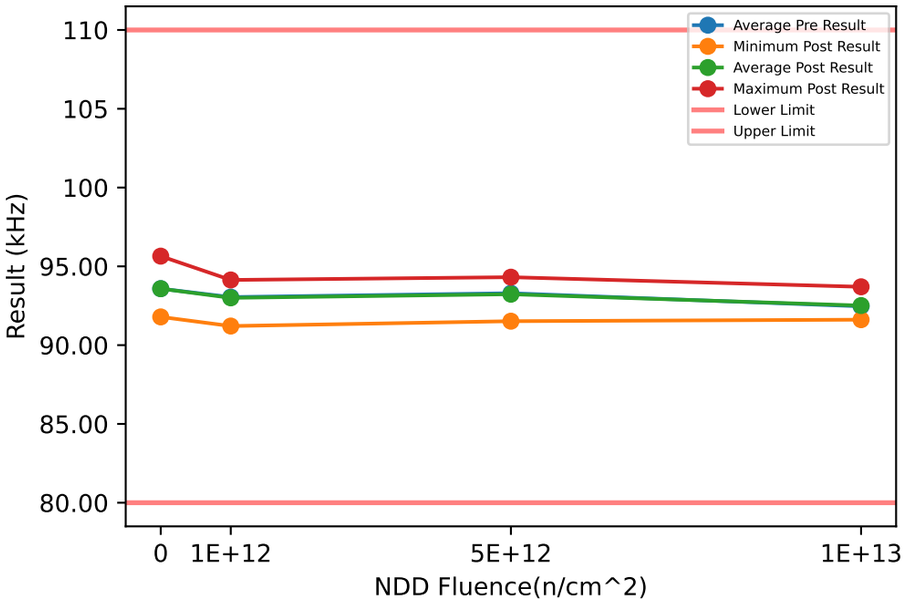
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.1235	2.3982	0.2747
466	1e+12	NDD	1.9269	1.9783	0.0514
762	0	CORRELATION	2.3255	2.4299	0.1044
769	1e+12	NDD	2.2532	2.2284	-0.0248
887	1e+12	NDD	2.3461	2.0284	-0.3177
891	0	CORRELATION	1.9869	2.0472	0.0603
927	1e+12	NDD	2.0745	2.3806	0.3061
967	5e+12	NDD	2.3647	1.8721	-0.4926
1204	1e+13	NDD	2.0177	1.9418	-0.0759
1284	1e+13	NDD	2.0941	2.161	0.0669
1292	5e+12	NDD	2.1034	2.0803	-0.0231
1364	1e+13	NDD	2.3118	2.2802	-0.0316
1383	5e+12	NDD	2.5363	2.5911	0.0548
1388	5e+12	NDD	2.0728	2.3271	0.2543
1427	1e+13	NDD	2.4622	2.166	-0.2962
1666	0	CORRELATION	2.4414	2.0523	-0.3891

Test Statistics ((1/fsw) s)

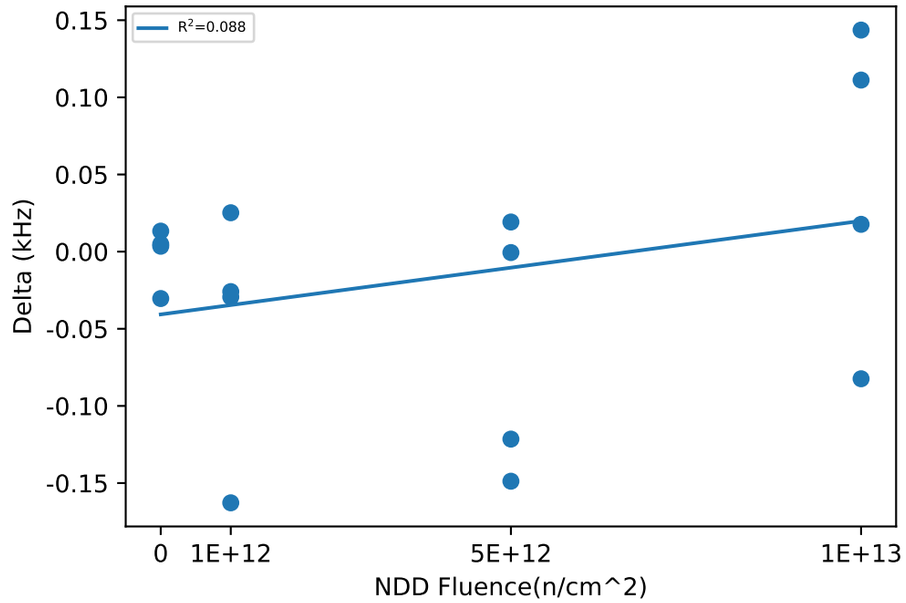
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9869	2.2193	2.4414	0.20314	2.0472	2.2319	2.4299	0.21074	-0.3891	0.012575	0.2747	0.28329
1e+12	1.9269	2.1502	2.3461	0.18671	1.9783	2.1539	2.3806	0.18577	-0.3177	0.00375	0.3061	0.2568
5e+12	2.0728	2.2693	2.5363	0.221	1.8721	2.2176	2.5911	0.31076	-0.4926	-0.05165	0.2543	0.31633
1e+13	2.0177	2.2214	2.4622	0.20319	1.9418	2.1372	2.2802	0.14145	-0.2962	-0.0842	0.0669	0.15342

Device Test: 20.15 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

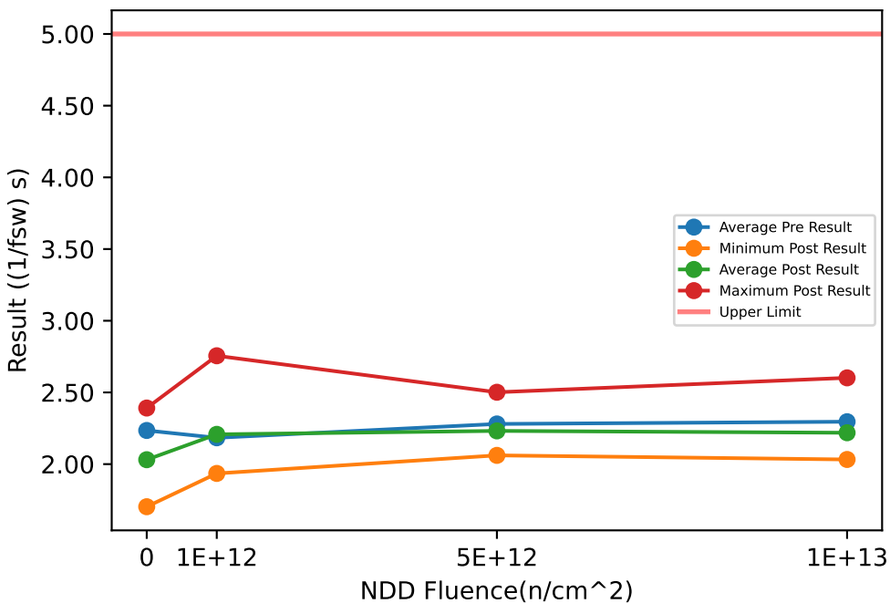
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	93.017	93.021	0.0035
466	1e+12	NDD	93.826	93.8	-0.0259
762	0	CORRELATION	91.787	91.791	0.0049
769	1e+12	NDD	92.885	92.856	-0.0294
887	1e+12	NDD	94.299	94.136	-0.1628
891	0	CORRELATION	95.634	95.648	0.0133
927	1e+12	NDD	91.186	91.211	0.0252
967	5e+12	NDD	94.292	94.311	0.0192
1204	1e+13	NDD	92.77	92.688	-0.0824
1284	1e+13	NDD	93.558	93.702	0.1436
1292	5e+12	NDD	93.141	92.992	-0.1488
1364	1e+13	NDD	91.504	91.615	0.1112
1383	5e+12	NDD	94.1	94.099	-0.0006
1388	5e+12	NDD	91.641	91.52	-0.1215
1427	1e+13	NDD	92.024	92.042	0.0177
1666	0	CORRELATION	93.897	93.867	-0.0304

Test Statistics (kHz)

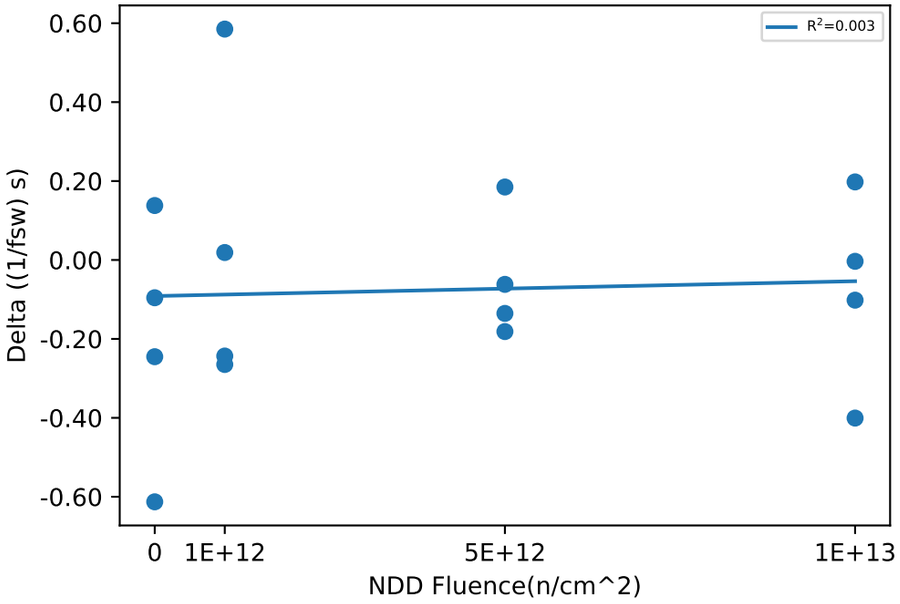
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.787	93.584	95.634	1.618	91.791	93.582	95.648	1.6196	-0.0304	-0.002175	0.0133	0.019308
1e+12	91.186	93.049	94.299	1.3739	91.211	93.001	94.136	1.3103	-0.1628	-0.048225	0.0252	0.080356
5e+12	91.641	93.294	94.292	1.2111	91.52	93.231	94.311	1.2788	-0.1488	-0.062925	0.0192	0.084527
1e+13	91.504	92.464	93.558	0.89574	91.615	92.512	93.702	0.90788	-0.0824	0.047525	0.1436	0.10174

Device Test: 20.150 FREQ|DETECTION/RT/14/14/0/0/5/100kHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



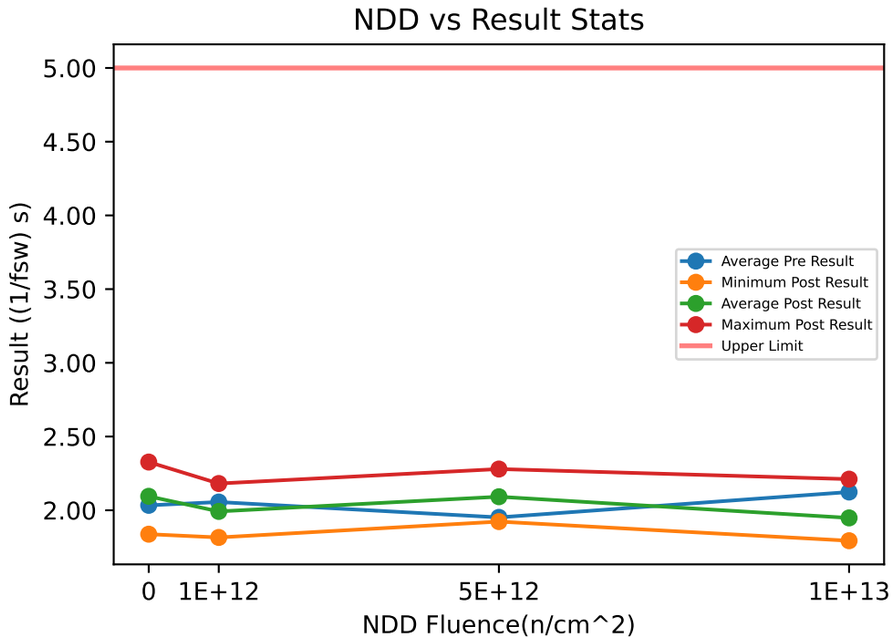
Test Results (Upper Limit = 5.0 ((1/fsw) s))

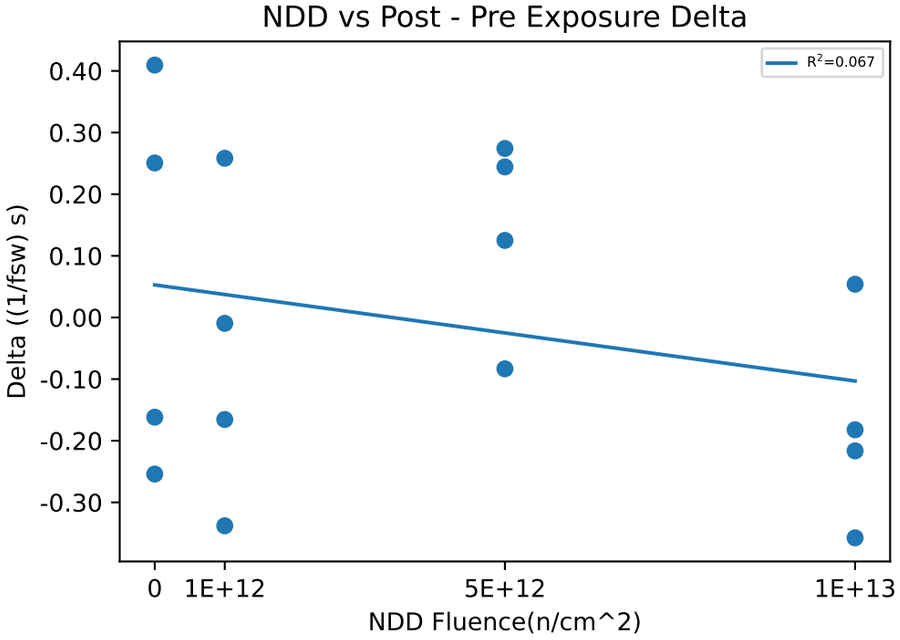
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.935	2.073	0.138
466	1e+12	NDD	1.9161	1.935	0.0189
762	0	CORRELATION	2.6363	2.3912	-0.2451
769	1e+12	NDD	2.2822	2.0388	-0.2434
887	1e+12	NDD	2.3659	2.1011	-0.2648
891	0	CORRELATION	2.0516	1.9559	-0.0957
927	1e+12	NDD	2.1706	2.7557	0.5851
967	5e+12	NDD	2.3528	2.1714	-0.1814
1204	1e+13	NDD	2.1664	2.163	-0.0034
1284	1e+13	NDD	2.1342	2.0324	-0.1018
1292	5e+12	NDD	2.1228	2.061	-0.0618
1364	1e+13	NDD	2.4039	2.6017	0.1978
1383	5e+12	NDD	2.3287	2.1933	-0.1354
1388	5e+12	NDD	2.3163	2.5012	0.1849
1427	1e+13	NDD	2.4784	2.0778	-0.4006
1666	0	CORRELATION	2.3157	1.7029	-0.6128

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.935	2.2347	2.6363	0.31155	1.7029	2.0307	2.3912	0.28566	-0.6128	-0.2039	0.138	0.31491
1e+12	1.9161	2.1837	2.3659	0.19552	1.935	2.2077	2.7557	0.37173	-0.2648	0.02395	0.5851	0.39571
5e+12	2.1228	2.2801	2.3528	0.10599	2.061	2.2317	2.5012	0.18875	-0.1814	-0.048425	0.1849	0.16316
1e+13	2.1342	2.2957	2.4784	0.17116	2.0324	2.2187	2.6017	0.26099	-0.4006	-0.077	0.1978	0.24917

Device Test: 20.152 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/200kHz//@T_INT_CLK_DET





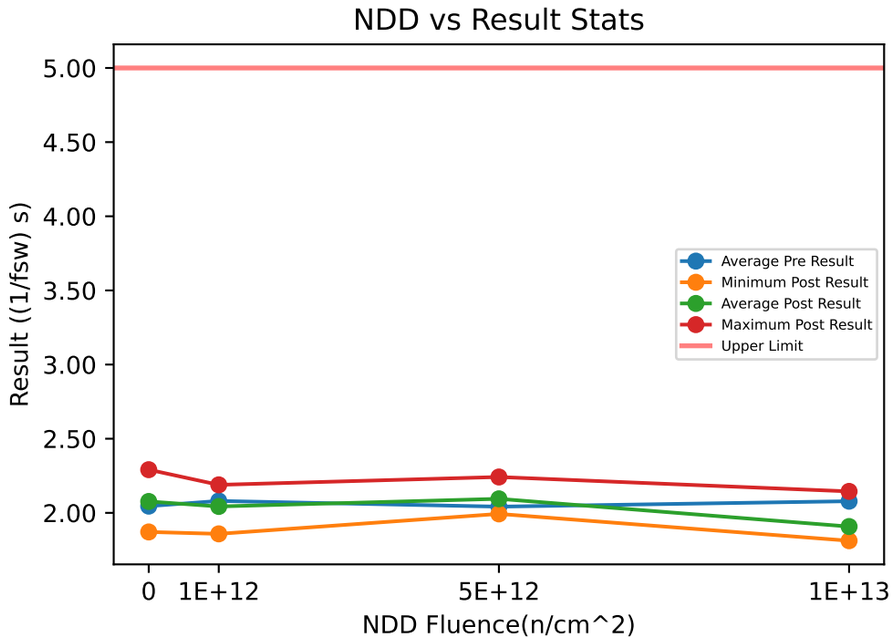
Test Results (Upper Limit = 5.0 ((1/fsw) s))

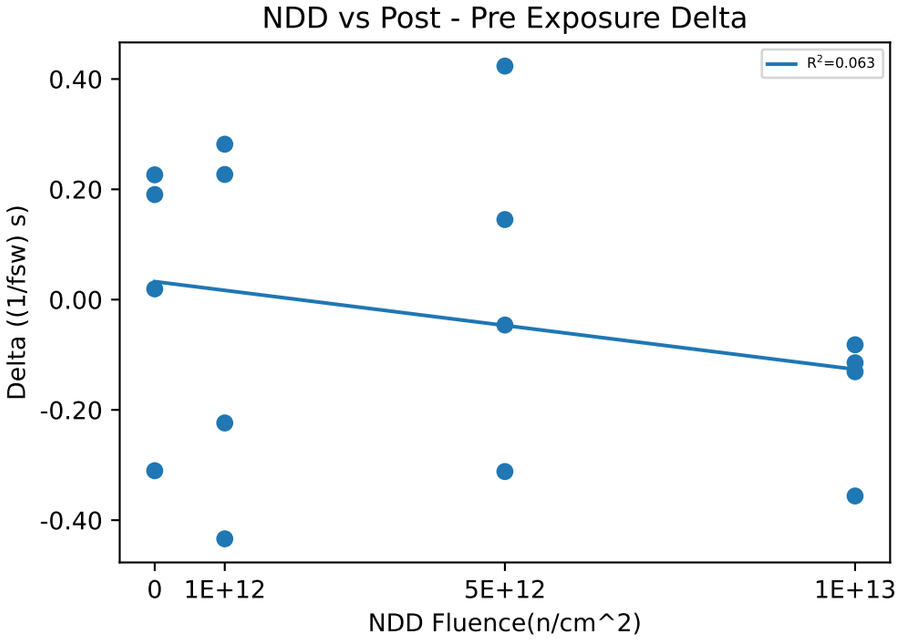
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.9175	2.327	0.4095
466	1e+12	NDD	1.943	1.9335	-0.0095
762	0	CORRELATION	2.0445	2.2952	0.2507
769	1e+12	NDD	2.2035	2.038	-0.1655
887	1e+12	NDD	2.1536	1.8156	-0.338
891	0	CORRELATION	1.9995	1.8377	-0.1618
927	1e+12	NDD	1.9231	2.1814	0.2583
967	5e+12	NDD	2.0892	2.0059	-0.0833
1204	1e+13	NDD	2.0098	1.7934	-0.2164
1284	1e+13	NDD	2.0978	1.9156	-0.1822
1292	5e+12	NDD	1.6788	1.9231	0.2443
1364	1e+13	NDD	2.1572	2.2111	0.0539
1383	5e+12	NDD	2.0054	2.2796	0.2742
1388	5e+12	NDD	2.0335	2.1585	0.125
1427	1e+13	NDD	2.2301	1.8726	-0.3575
1666	0	CORRELATION	2.1725	1.9185	-0.254

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9175	2.0335	2.1725	0.10654	1.8377	2.0946	2.327	0.25249	-0.254	0.0611	0.4095	0.31953
1e+12	1.9231	2.0558	2.2035	0.14343	1.8156	1.9921	2.1814	0.15549	-0.338	-0.063675	0.2583	0.25313
5e+12	1.6788	1.9517	2.0892	0.18525	1.9231	2.0918	2.2796	0.1587	-0.0833	0.14005	0.2742	0.16225
1e+13	2.0098	2.1237	2.2301	0.093251	1.7934	1.9482	2.2111	0.18244	-0.3575	-0.17555	0.0539	0.17075

Device Test: 20.154 FREQ|DETECTION/RT/5/5/0/0/5/200kHz//@T_INT_CLK_DET





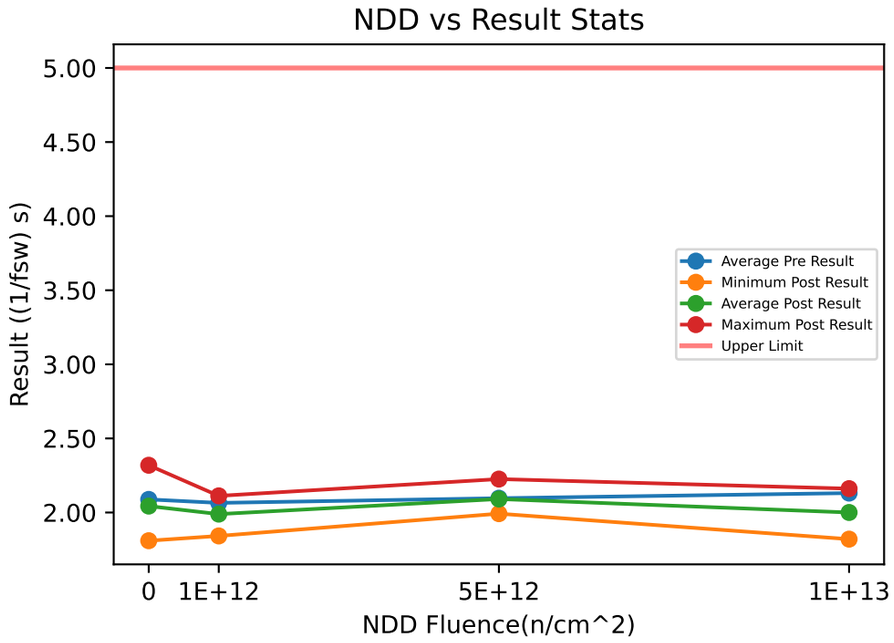
Test Results (Upper Limit = 5.0 ((1/fsw) s))

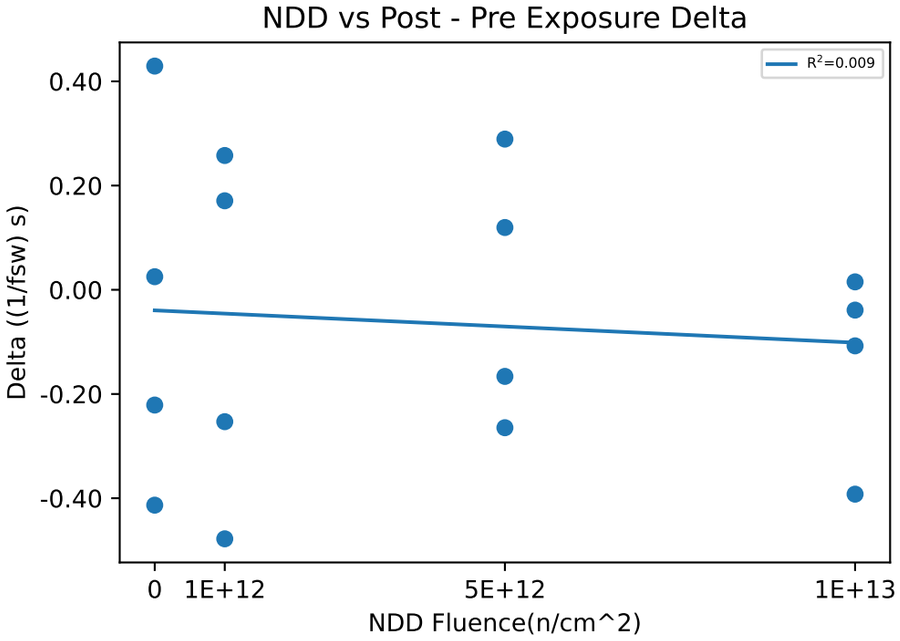
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.9184	2.1447	0.2263
466	1e+12	NDD	1.8676	2.1494	0.2818
762	0	CORRELATION	2.2717	2.2911	0.0194
769	1e+12	NDD	2.2922	1.8584	-0.4338
887	1e+12	NDD	2.1995	1.9758	-0.2237
891	0	CORRELATION	1.8097	2.0002	0.1905
927	1e+12	NDD	1.962	2.1889	0.2269
967	5e+12	NDD	2.3048	1.993	-0.3118
1204	1e+13	NDD	1.9564	1.8419	-0.1145
1284	1e+13	NDD	1.894	1.8121	-0.0819
1292	5e+12	NDD	1.8547	1.9999	0.1452
1364	1e+13	NDD	2.2755	2.1447	-0.1308
1383	5e+12	NDD	2.1898	2.1437	-0.0461
1388	5e+12	NDD	1.8183	2.2418	0.4235
1427	1e+13	NDD	2.1884	1.8323	-0.3561
1666	0	CORRELATION	2.1815	1.8712	-0.3103

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8097	2.0453	2.2717	0.21712	1.8712	2.0768	2.2911	0.18136	-0.3103	0.031475	0.2263	0.24509
1e+12	1.8676	2.0803	2.2922	0.19862	1.8584	2.0431	2.1889	0.15406	-0.4338	-0.0372	0.2818	0.34813
5e+12	1.8183	2.0419	2.3048	0.24223	1.993	2.0946	2.2418	0.12023	-0.3118	0.0527	0.4235	0.3102
1e+13	1.894	2.0786	2.2755	0.18242	1.8121	1.9078	2.1447	0.15845	-0.3561	-0.17083	-0.0819	0.12518

Device Test: 20.156 FREQ|DETECTION/RT/12/12/0/0/5/200kHz//@T_INT_CLK_DET





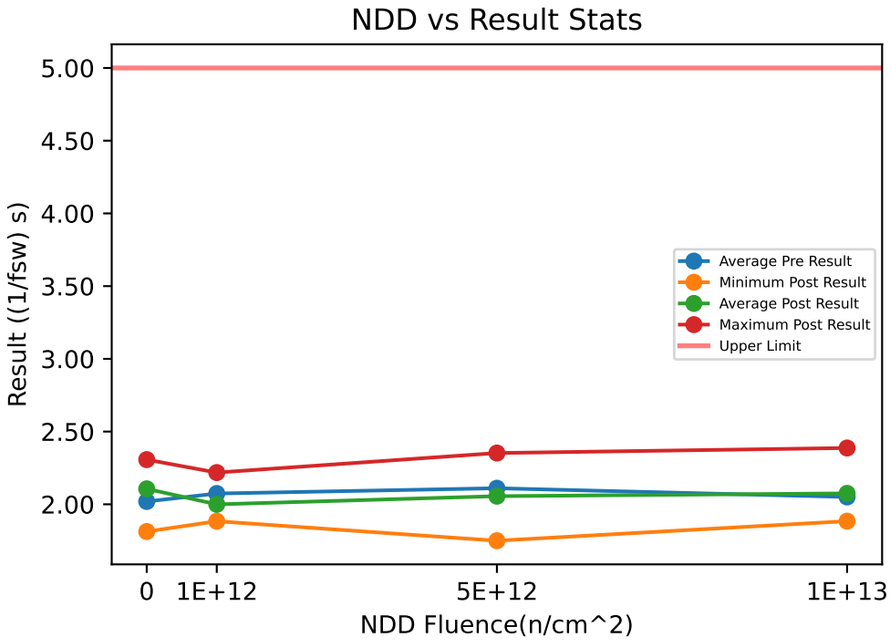
Test Results (Upper Limit = 5.0 ((1/fsw) s))

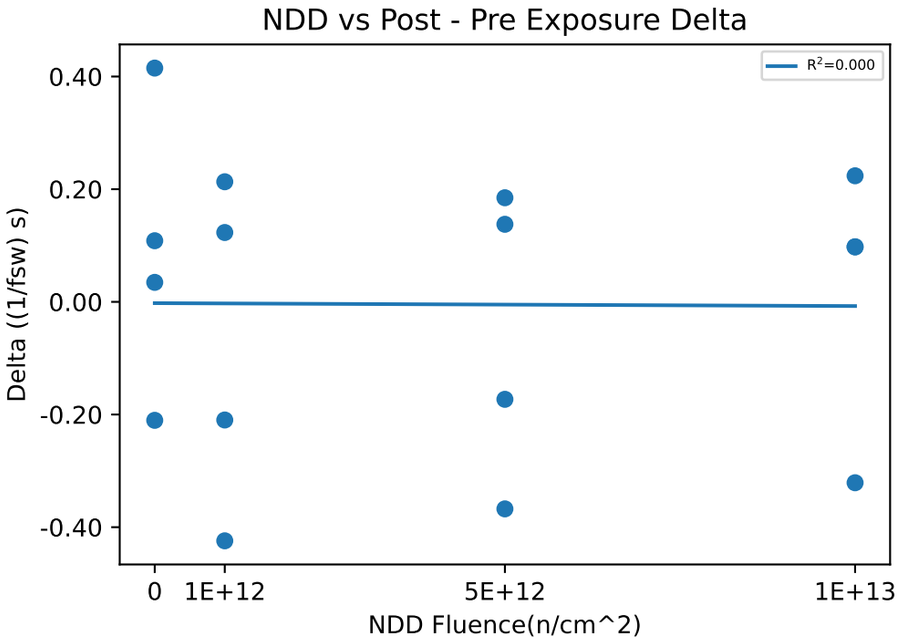
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.8896	2.3189	0.4293
466	1e+12	NDD	1.8923	2.0631	0.1708
762	0	CORRELATION	2.1513	2.1764	0.0251
769	1e+12	NDD	2.3198	1.8419	-0.4779
887	1e+12	NDD	2.1928	1.9397	-0.2531
891	0	CORRELATION	2.0896	1.8684	-0.2212
927	1e+12	NDD	1.8546	2.1123	0.2577
967	5e+12	NDD	2.1584	1.9922	-0.1662
1204	1e+13	NDD	2.002	2.0172	0.0152
1284	1e+13	NDD	1.9279	1.8203	-0.1076
1292	5e+12	NDD	1.8877	2.0072	0.1195
1364	1e+13	NDD	2.2001	2.1611	-0.039
1383	5e+12	NDD	2.4034	2.1387	-0.2647
1388	5e+12	NDD	1.9364	2.2256	0.2892
1427	1e+13	NDD	2.3942	2.002	-0.3922
1666	0	CORRELATION	2.2229	1.8096	-0.4133

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8896	2.0884	2.2229	0.14326	1.8096	2.0433	2.3189	0.24418	-0.4133	-0.045025	0.4293	0.36358
1e+12	1.8546	2.0649	2.3198	0.22756	1.8419	1.9892	2.1123	0.12215	-0.4779	-0.075625	0.2577	0.34888
5e+12	1.8877	2.0965	2.4034	0.23611	1.9922	2.0909	2.2256	0.11132	-0.2647	-0.00555	0.2892	0.25527
1e+13	1.9279	2.1311	2.3942	0.20971	1.8203	2.0001	2.1611	0.1397	-0.3922	-0.1309	0.0152	0.1813

Device Test: 20.158 FREQ|DETECTION/RT/14/14/0/0/5/200kHz//@T_INT_CLK_DET





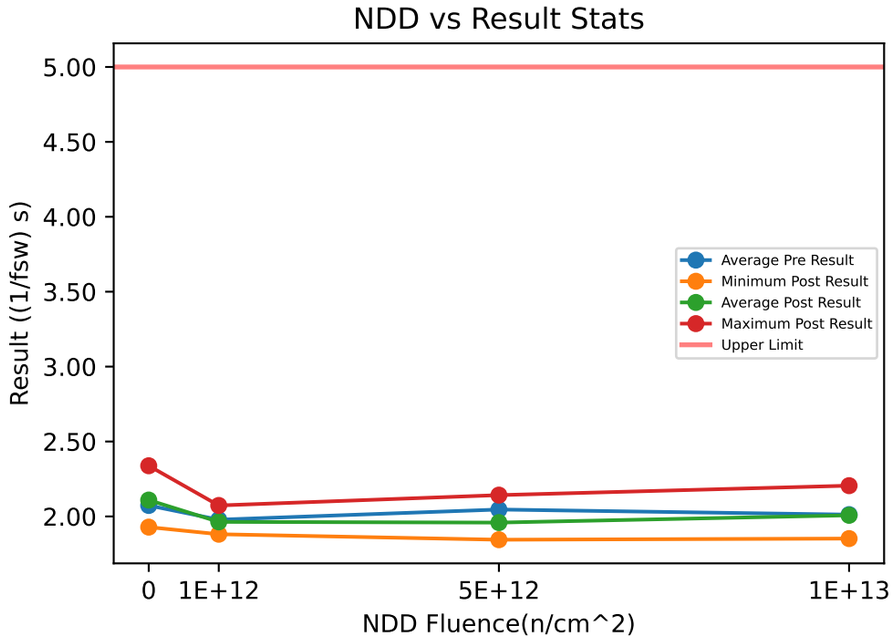
Test Results (Upper Limit = 5.0 ((1/fsw) s))

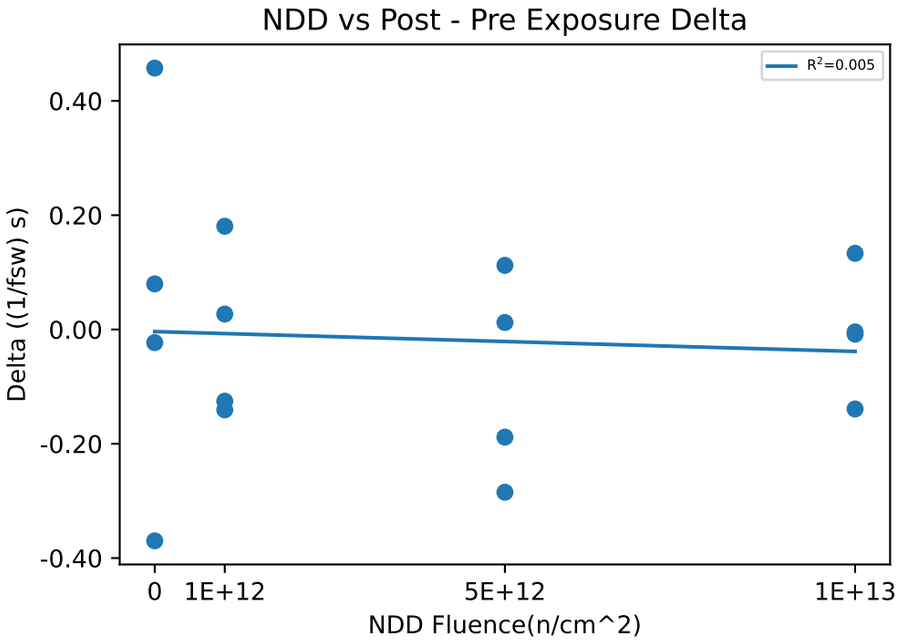
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.8517	2.2667	0.415
466	1e+12	NDD	1.798	1.9211	0.1231
762	0	CORRELATION	2.2725	2.3071	0.0346
769	1e+12	NDD	2.3077	1.8835	-0.4242
887	1e+12	NDD	2.1853	1.9756	-0.2097
891	0	CORRELATION	1.9301	2.0386	0.1085
927	1e+12	NDD	2.0049	2.2181	0.2132
967	5e+12	NDD	2.2925	1.925	-0.3675
1204	1e+13	NDD	1.8615	1.9593	0.0978
1284	1e+13	NDD	1.9721	2.0696	0.0975
1292	5e+12	NDD	1.9225	1.7495	-0.173
1364	1e+13	NDD	2.1632	2.387	0.2238
1383	5e+12	NDD	2.2147	2.3524	0.1377
1388	5e+12	NDD	2.0117	2.1965	0.1848
1427	1e+13	NDD	2.2051	1.884	-0.3211
1666	0	CORRELATION	2.0228	1.8125	-0.2103

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8517	2.0193	2.2725	0.18273	1.8125	2.1062	2.3071	0.22873	-0.2103	0.08695	0.415	0.25767
1e+12	1.798	2.074	2.3077	0.22208	1.8835	1.9996	2.2181	0.15051	-0.4242	-0.0744	0.2132	0.29574
5e+12	1.9225	2.1103	2.2925	0.17232	1.7495	2.0558	2.3524	0.27	-0.3675	-0.0545	0.1848	0.26218
1e+13	1.8615	2.0505	2.2051	0.16173	1.884	2.075	2.387	0.22154	-0.3211	0.0245	0.2238	0.23795

Device Test: 20.160 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/500kHz//@T_INT_CLK_DET





Test Results (Upper Limit = 5.0 ((1/fsw) s))

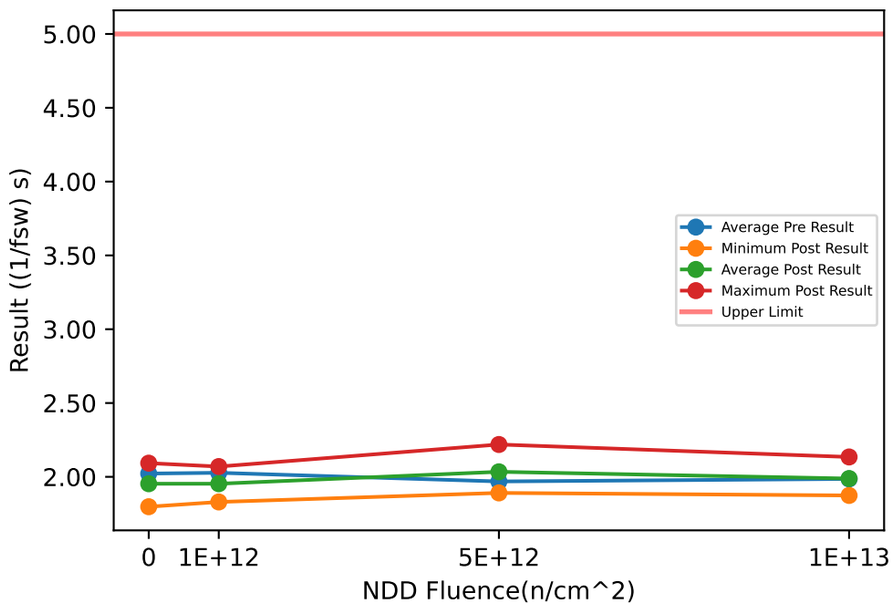
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.8808	2.3382	0.4574
466	1e+12	NDD	1.8925	2.0731	0.1806
762	0	CORRELATION	2.1394	2.2192	0.0798
769	1e+12	NDD	2.0218	1.8812	-0.1406
887	1e+12	NDD	2.1114	1.9859	-0.1255
891	0	CORRELATION	1.9516	1.9286	-0.023
927	1e+12	NDD	1.8872	1.9142	0.027
967	5e+12	NDD	2.1293	1.8445	-0.2848
1204	1e+13	NDD	1.9912	1.8521	-0.1391
1284	1e+13	NDD	1.9225	2.0558	0.1333
1292	5e+12	NDD	2.0538	1.8654	-0.1884
1364	1e+13	NDD	2.2135	2.2053	-0.0082
1383	5e+12	NDD	1.9712	1.9834	0.0122
1388	5e+12	NDD	2.03	2.1422	0.1122
1427	1e+13	NDD	1.921	1.9167	-0.0043
1666	0	CORRELATION	2.3206	1.9508	-0.3698

Test Statistics ((1/fsw) s)

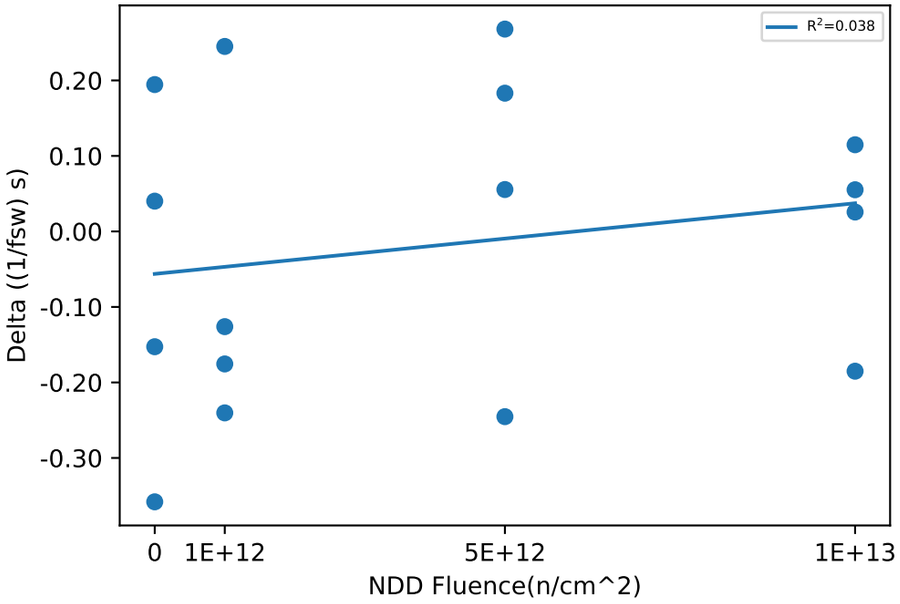
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8808	2.0731	2.3206	0.19782	1.9286	2.1092	2.3382	0.20186	-0.3698	0.0361	0.4574	0.34042
1e+12	1.8872	1.9782	2.1114	0.10843	1.8812	1.9636	2.0731	0.085084	-0.1406	-0.014625	0.1806	0.15056
5e+12	1.9712	2.0461	2.1293	0.065449	1.8445	1.9589	2.1422	0.13666	-0.2848	-0.0872	0.1122	0.18159
1e+13	1.921	2.012	2.2135	0.13823	1.8521	2.0075	2.2053	0.1569	-0.1391	-0.004575	0.1333	0.11124

Device Test: 20.162 FREQ|DETECTION/RT/5/5/0/0/5/500kHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

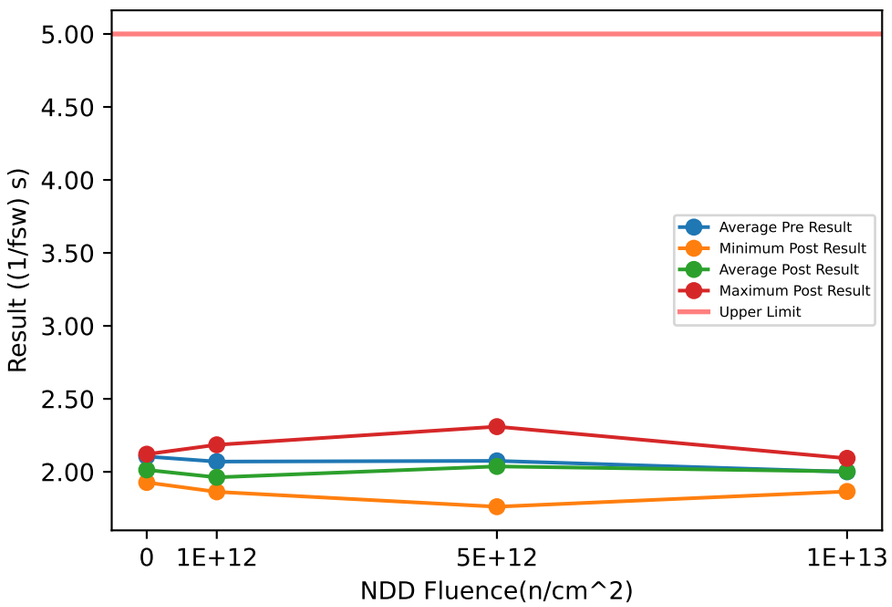
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.8981	2.0926	0.1945
466	1e+12	NDD	1.9558	1.8297	-0.1261
762	0	CORRELATION	2.05	2.0901	0.0401
769	1e+12	NDD	2.2659	2.0256	-0.2403
887	1e+12	NDD	2.0633	1.8878	-0.1755
891	0	CORRELATION	2.1556	1.7975	-0.3581
927	1e+12	NDD	1.8246	2.0696	0.245
967	5e+12	NDD	2.1363	1.891	-0.2453
1204	1e+13	NDD	1.8482	1.8739	0.0257
1284	1e+13	NDD	1.8765	1.9913	0.1148
1292	5e+12	NDD	1.8722	1.9277	0.0555
1364	1e+13	NDD	2.0793	2.1345	0.0552
1383	5e+12	NDD	1.9154	2.0985	0.1831
1388	5e+12	NDD	1.951	2.219	0.268
1427	1e+13	NDD	2.139	1.9539	-0.1851
1666	0	CORRELATION	1.9851	1.8324	-0.1527

Test Statistics ((1/fsw) s)

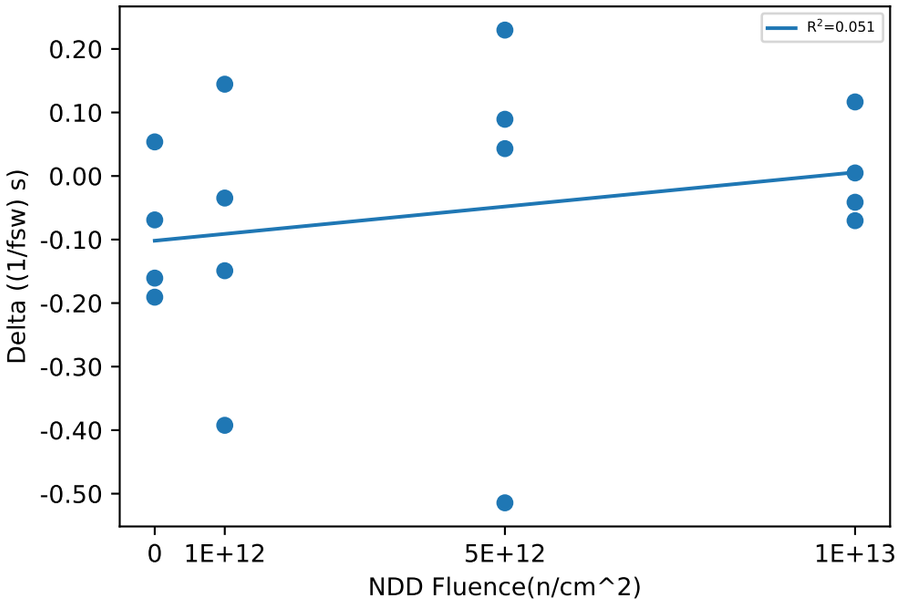
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8981	2.0222	2.1556	0.10854	1.7975	1.9531	2.0926	0.16022	-0.3581	-0.06905	0.1945	0.23939
1e+12	1.8246	2.0274	2.2659	0.18657	1.8297	1.9532	2.0696	0.11302	-0.2403	-0.074225	0.245	0.21789
5e+12	1.8722	1.9687	2.1363	0.11627	1.891	2.0341	2.219	0.1529	-0.2453	0.065325	0.268	0.22475
1e+13	1.8482	1.9857	2.139	0.14502	1.8739	1.9884	2.1345	0.10902	-0.1851	0.00265	0.1148	0.13054

Device Test: 20.164 FREQ|DETECTION/RT/12/12/0/0/5/500kHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

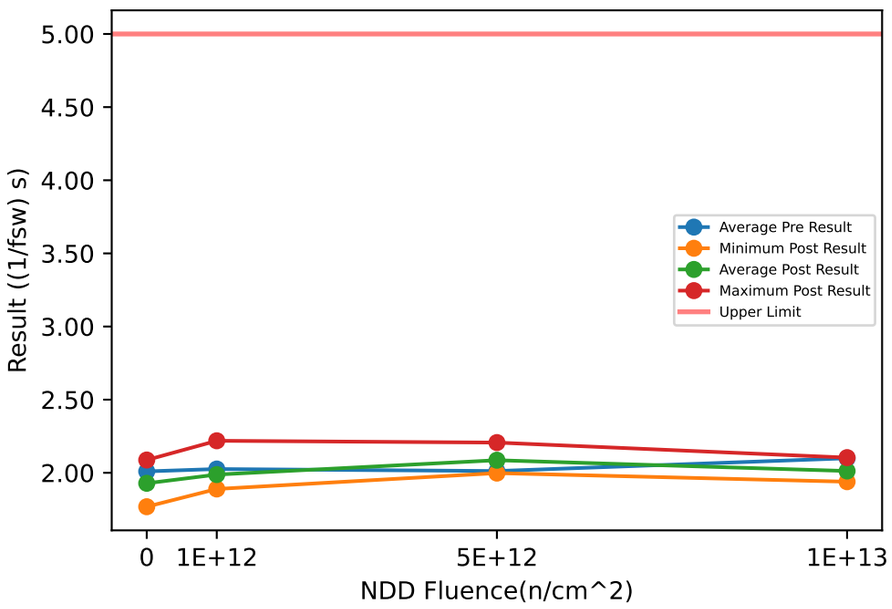
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.0673	2.121	0.0537
466	1e+12	NDD	1.903	1.8683	-0.0347
762	0	CORRELATION	2.2041	2.0134	-0.1907
769	1e+12	NDD	2.0821	1.933	-0.1491
887	1e+12	NDD	2.2553	1.8629	-0.3924
891	0	CORRELATION	1.9964	1.9273	-0.0691
927	1e+12	NDD	2.0407	2.1852	0.1445
967	5e+12	NDD	2.2754	1.761	-0.5144
1204	1e+13	NDD	1.9068	1.8655	-0.0413
1284	1e+13	NDD	1.8937	2.0103	0.1166
1292	5e+12	NDD	1.7814	1.8707	0.0893
1364	1e+13	NDD	2.1629	2.0926	-0.0703
1383	5e+12	NDD	2.164	2.2071	0.0431
1388	5e+12	NDD	2.0799	2.3096	0.2297
1427	1e+13	NDD	2.0369	2.0417	0.0048
1666	0	CORRELATION	2.1518	1.9911	-0.1607

Test Statistics ((1/fsw) s)

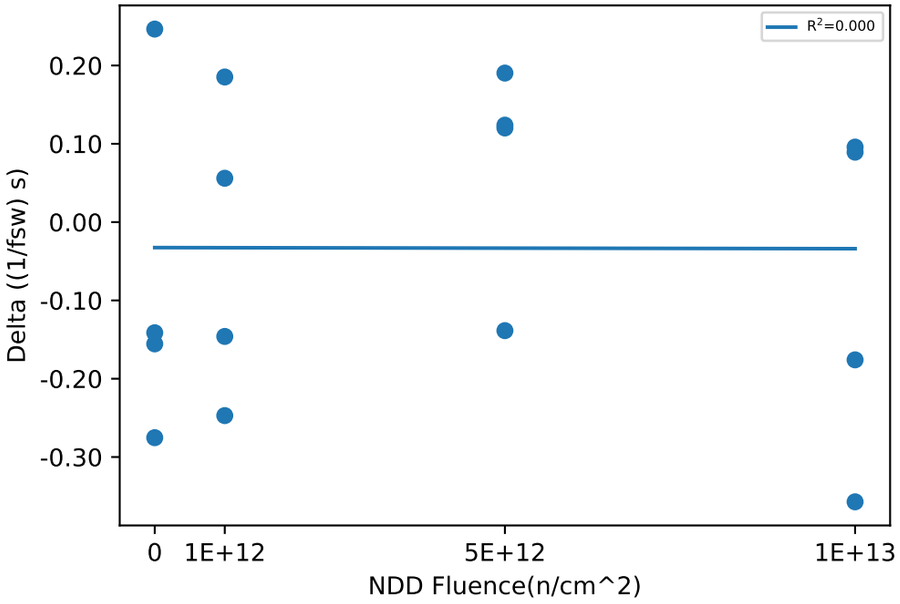
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9964	2.1049	2.2041	0.091699	1.9273	2.0132	2.121	0.080598	-0.1907	-0.0917	0.0537	0.10987
1e+12	1.903	2.0703	2.2553	0.14518	1.8629	1.9624	2.1852	0.15194	-0.3924	-0.10793	0.1445	0.22487
5e+12	1.7814	2.0752	2.2754	0.21159	1.761	2.0371	2.3096	0.26273	-0.5144	-0.038075	0.2297	0.32731
1e+13	1.8937	2.0001	2.1629	0.12634	1.8655	2.0025	2.0926	0.097441	-0.0703	0.00245	0.1166	0.082143

Device Test: 20.166 FREQ|DETECTION/RT/14/14/0/0/5/500kHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



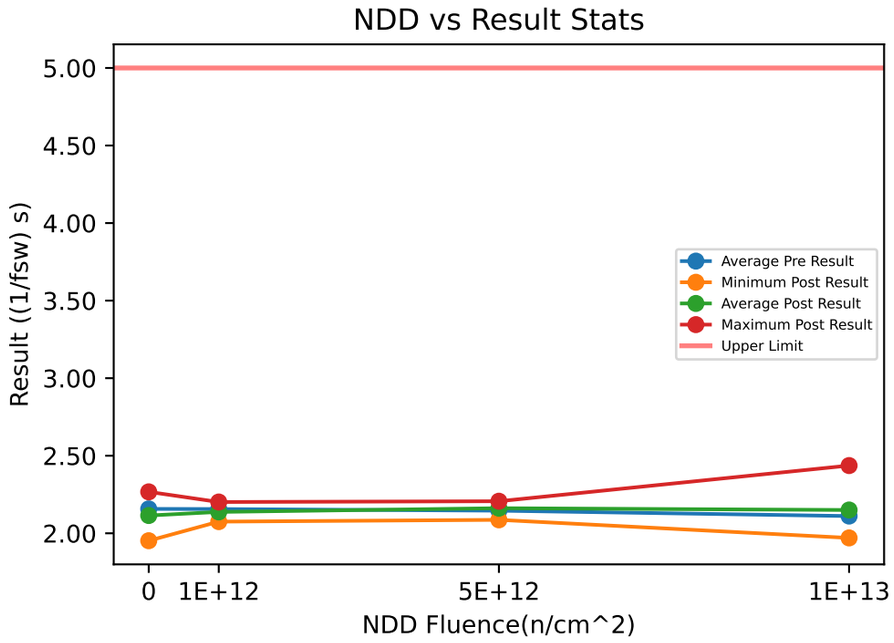
Test Results (Upper Limit = 5.0 ((1/fsw) s))

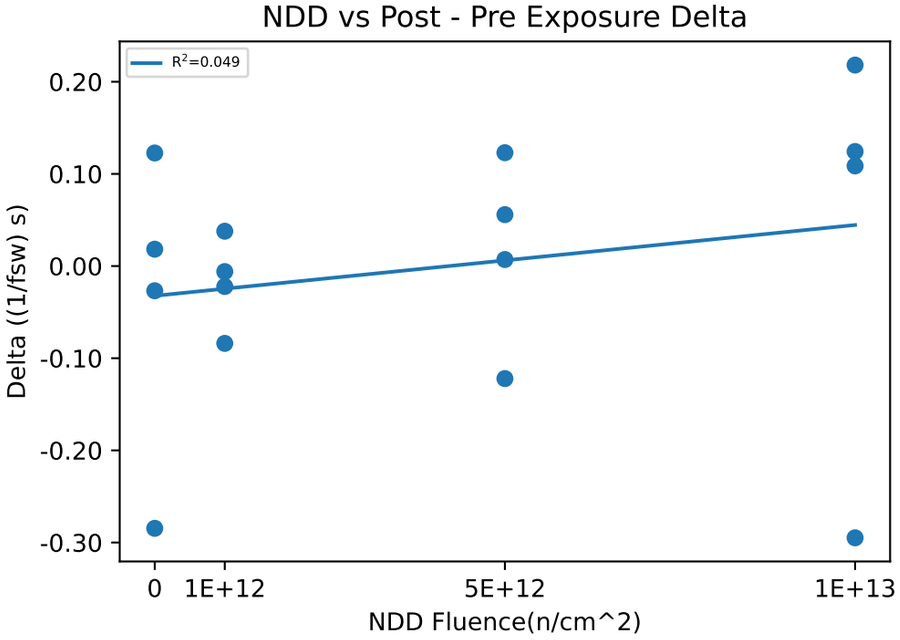
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.8409	2.0874	0.2465
466	1e+12	NDD	1.8788	1.9348	0.056
762	0	CORRELATION	2.2274	2.0719	-0.1555
769	1e+12	NDD	2.1553	1.9082	-0.2471
887	1e+12	NDD	2.0354	1.8894	-0.146
891	0	CORRELATION	1.927	1.7857	-0.1413
927	1e+12	NDD	2.0336	2.2189	0.1853
967	5e+12	NDD	2.1365	1.9979	-0.1386
1204	1e+13	NDD	1.9122	2.0015	0.0893
1284	1e+13	NDD	1.9089	2.0047	0.0958
1292	5e+12	NDD	1.9133	2.0371	0.1238
1364	1e+13	NDD	2.2797	2.1038	-0.1759
1383	5e+12	NDD	2.0864	2.2066	0.1202
1388	5e+12	NDD	1.9122	2.1025	0.1903
1427	1e+13	NDD	2.2963	1.9391	-0.3572
1666	0	CORRELATION	2.0434	1.7681	-0.2753

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.8409	2.0097	2.2274	0.16719	1.7681	1.9283	2.0874	0.17505	-0.2753	-0.0814	0.2465	0.22671
1e+12	1.8788	2.0258	2.1553	0.11333	1.8894	1.9878	2.2189	0.15517	-0.2471	-0.03795	0.1853	0.19501
5e+12	1.9122	2.0121	2.1365	0.11653	1.9979	2.086	2.2066	0.091231	-0.1386	0.073925	0.1903	0.1453
1e+13	1.9089	2.0993	2.2963	0.21803	1.9391	2.0123	2.1038	0.068081	-0.3572	-0.087	0.0958	0.22016

Device Test: 20.168 FREQ|DETECTION/RT/4.5/4.5/0/0/4.5/1MHz//@T_INT_CLK_DET





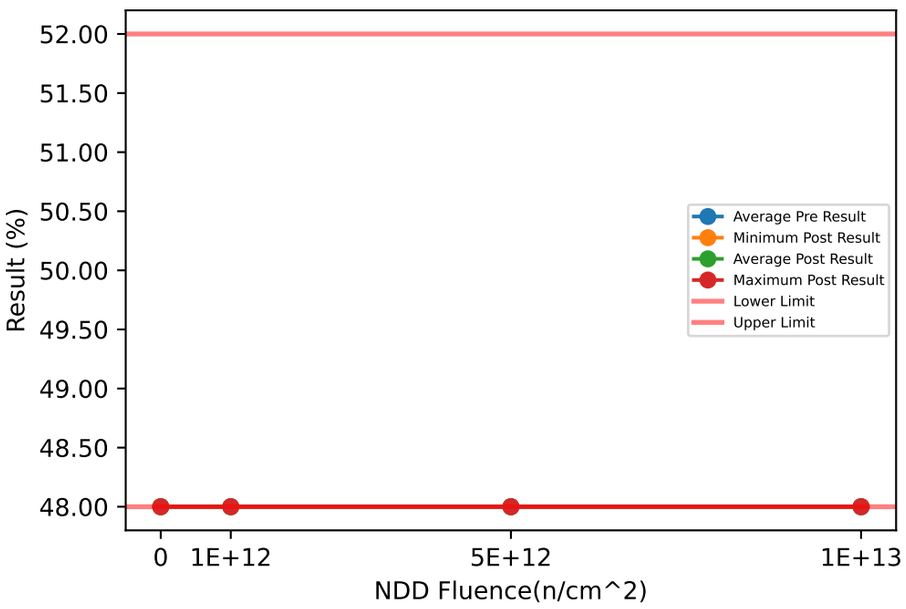
Test Results (Upper Limit = 5.0 ((1/fsw) s))

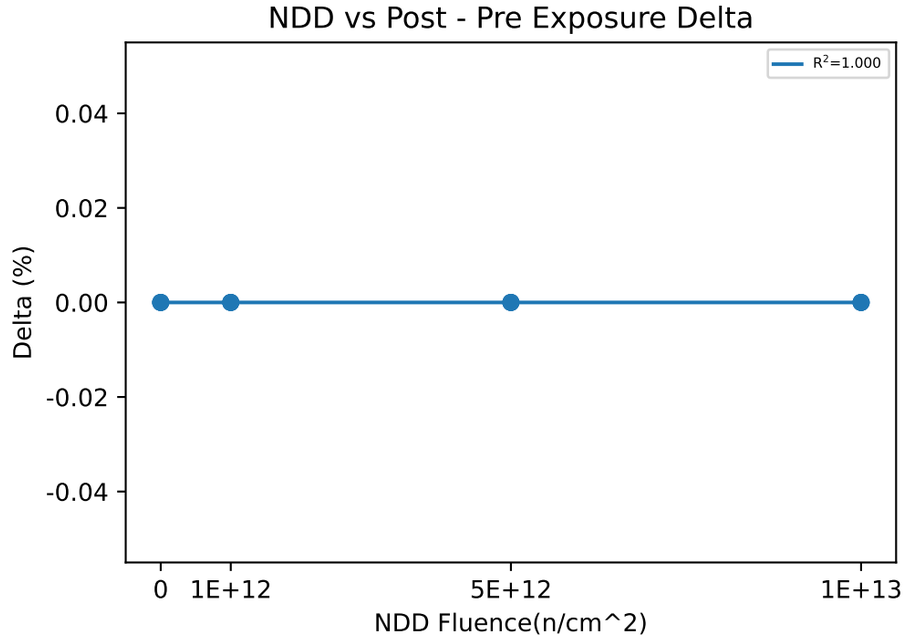
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.2006	2.2189	0.0183
466	1e+12	NDD	2.0758	2.1136	0.0378
762	0	CORRELATION	2.1444	2.2671	0.1227
769	1e+12	NDD	2.1665	2.1605	-0.006
887	1e+12	NDD	2.1591	2.0752	-0.0839
891	0	CORRELATION	1.9789	1.9521	-0.0268
927	1e+12	NDD	2.2238	2.2016	-0.0222
967	5e+12	NDD	2.2699	2.1478	-0.1221
1204	1e+13	NDD	1.9227	2.047	0.1243
1284	1e+13	NDD	2.0381	2.1468	0.1087
1292	5e+12	NDD	1.9637	2.0867	0.123
1364	1e+13	NDD	2.2185	2.4366	0.2181
1383	5e+12	NDD	2.1996	2.2067	0.0071
1388	5e+12	NDD	2.1501	2.2059	0.0558
1427	1e+13	NDD	2.2651	1.9702	-0.2949
1666	0	CORRELATION	2.305	2.0204	-0.2846

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9789	2.1572	2.305	0.13624	1.9521	2.1146	2.2671	0.15211	-0.2846	-0.0426	0.1227	0.17306
1e+12	2.0758	2.1563	2.2238	0.06096	2.0752	2.1377	2.2016	0.055046	-0.0839	-0.018575	0.0378	0.050388
5e+12	1.9637	2.1458	2.2699	0.13099	2.0867	2.1618	2.2067	0.057146	-0.1221	0.01595	0.123	0.10358
1e+13	1.9227	2.1111	2.2651	0.15924	1.9702	2.1502	2.4366	0.20419	-0.2949	0.03905	0.2181	0.22782

Device Test: 20.17 PF|DCL_48/SYNC/4.5/4.5/0/0/4.5/100kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

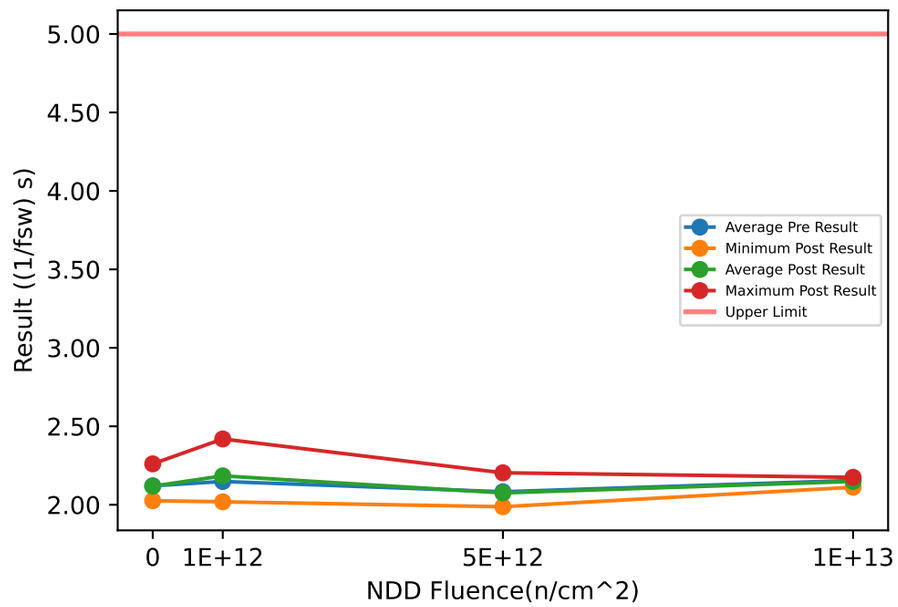
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

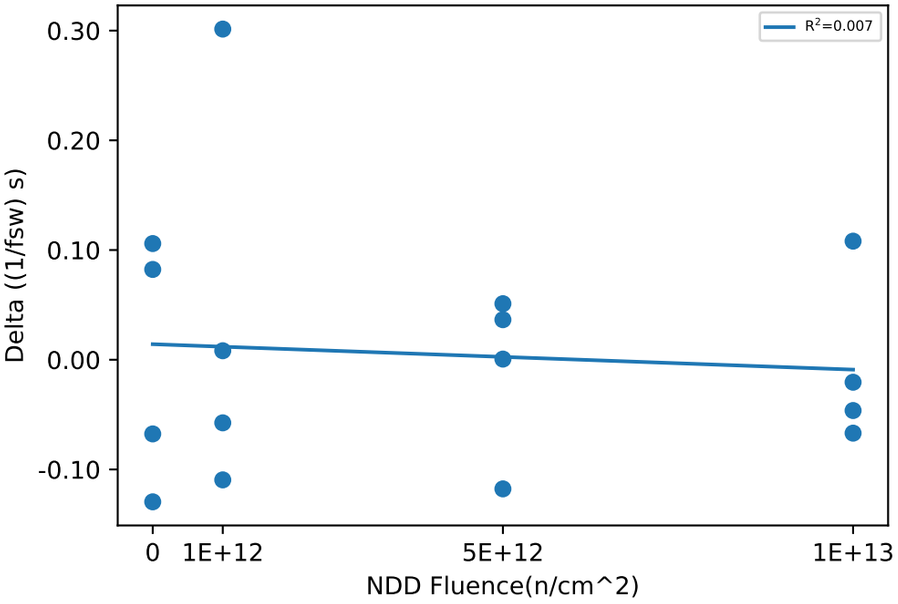
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.170 FREQ|DETECTION/RT/5/5/0/0/5/1MHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

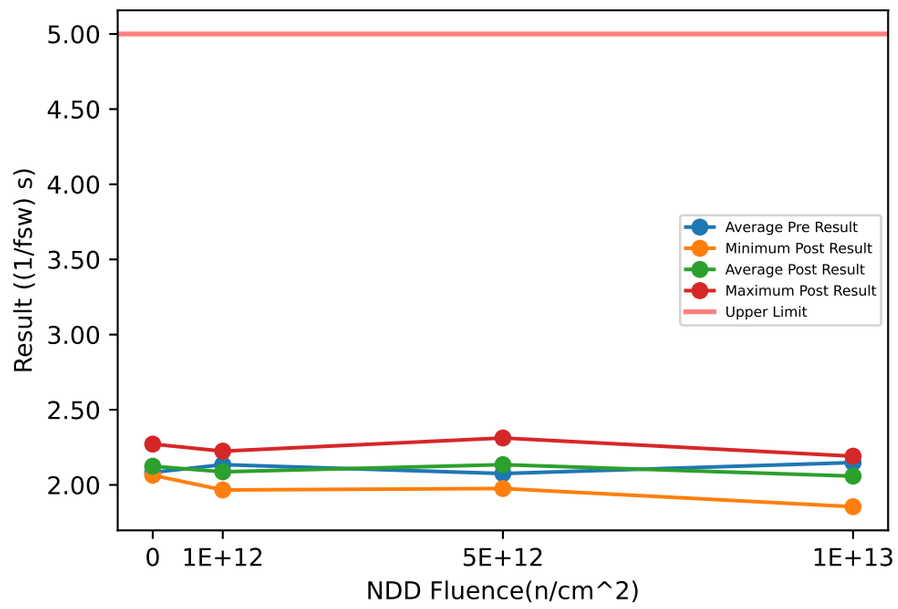
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.2347	2.1052	-0.1295
466	1e+12	NDD	2.0968	2.105	0.0082
762	0	CORRELATION	2.1548	2.2607	0.1059
769	1e+12	NDD	2.2505	2.193	-0.0575
887	1e+12	NDD	2.1285	2.019	-0.1095
891	0	CORRELATION	1.9436	2.0259	0.0823
927	1e+12	NDD	2.118	2.4194	0.3014
967	5e+12	NDD	2.1053	1.9876	-0.1177
1204	1e+13	NDD	2.0314	2.1395	0.1081
1284	1e+13	NDD	2.1787	2.1118	-0.0669
1292	5e+12	NDD	2.0335	2.07	0.0365
1364	1e+13	NDD	2.1887	2.1682	-0.0205
1383	5e+12	NDD	2.2031	2.2037	0.0006
1388	5e+12	NDD	1.9897	2.0408	0.0511
1427	1e+13	NDD	2.2212	2.1749	-0.0463
1666	0	CORRELATION	2.1496	2.082	-0.0676

Test Statistics ((1/fsw) s)

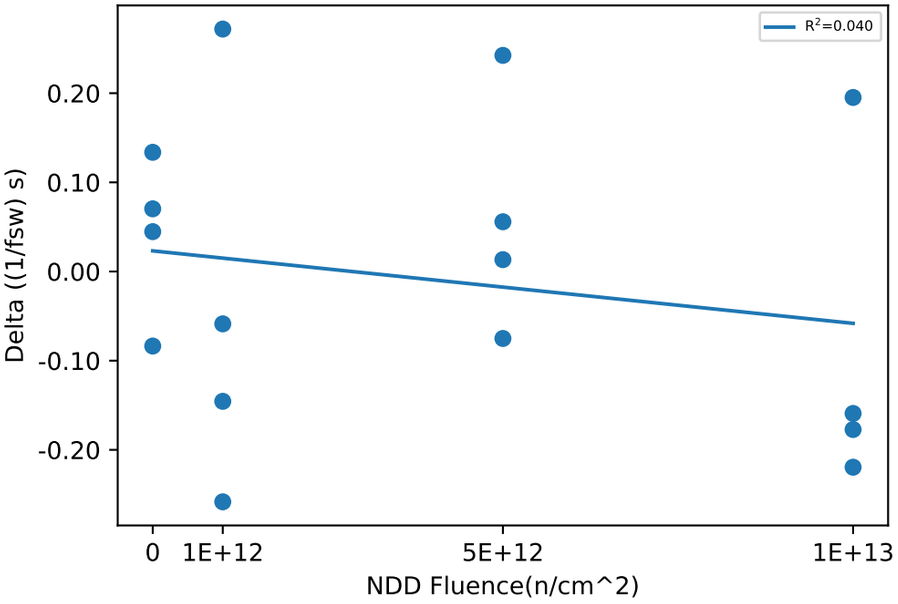
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9436	2.1207	2.2347	0.12431	2.0259	2.1185	2.2607	0.10051	-0.1295	-0.002225	0.1059	0.11447
1e+12	2.0968	2.1484	2.2505	0.069299	2.019	2.1841	2.4194	0.1722	-0.1095	0.03565	0.3014	0.1836
5e+12	1.9897	2.0829	2.2031	0.093232	1.9876	2.0755	2.2037	0.092007	-0.1177	-0.007375	0.0511	0.07655
1e+13	2.0314	2.155	2.2212	0.084374	2.1118	2.1486	2.1749	0.028942	-0.0669	-0.0064	0.1081	0.078658

Device Test: 20.172 FREQ|DETECTION/RT/12/12/0/0/5/1MHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 5.0 ((1/fsw) s))

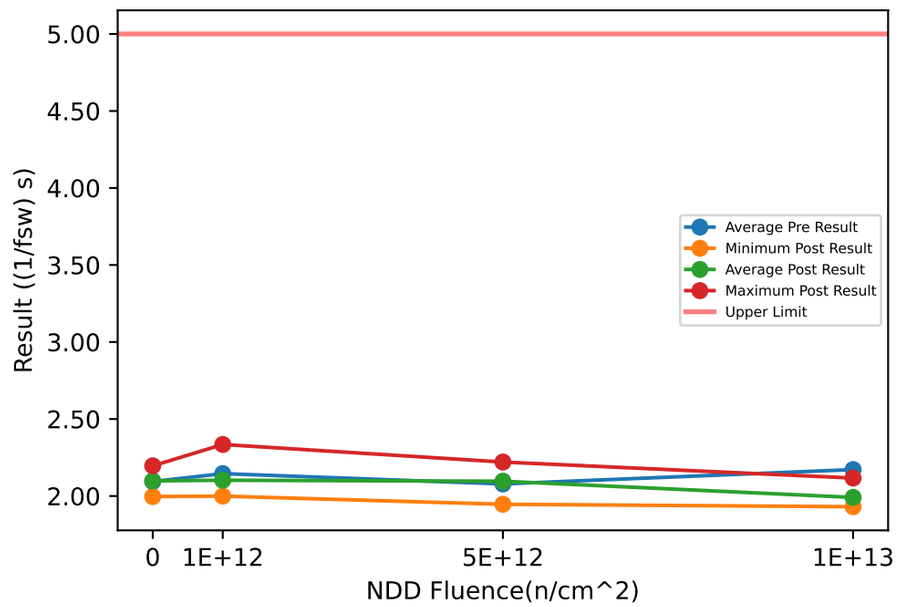
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.9564	2.0901	0.1337
466	1e+12	NDD	2.1659	2.0203	-0.1456
762	0	CORRELATION	2.2012	2.2715	0.0703
769	1e+12	NDD	2.2247	1.9664	-0.2583
887	1e+12	NDD	2.196	2.1373	-0.0587
891	0	CORRELATION	2.0197	2.0644	0.0447
927	1e+12	NDD	1.9527	2.2246	0.2719
967	5e+12	NDD	1.9627	1.976	0.0133
1204	1e+13	NDD	1.9009	2.0961	0.1952
1284	1e+13	NDD	2.0141	1.8549	-0.1592
1292	5e+12	NDD	2.0683	1.9932	-0.0751
1364	1e+13	NDD	2.3683	2.1911	-0.1772
1383	5e+12	NDD	2.2015	2.2573	0.0558
1388	5e+12	NDD	2.0698	2.3122	0.2424
1427	1e+13	NDD	2.311	2.0915	-0.2195
1666	0	CORRELATION	2.1549	2.0713	-0.0836

Test Statistics ((1/fsw) s)

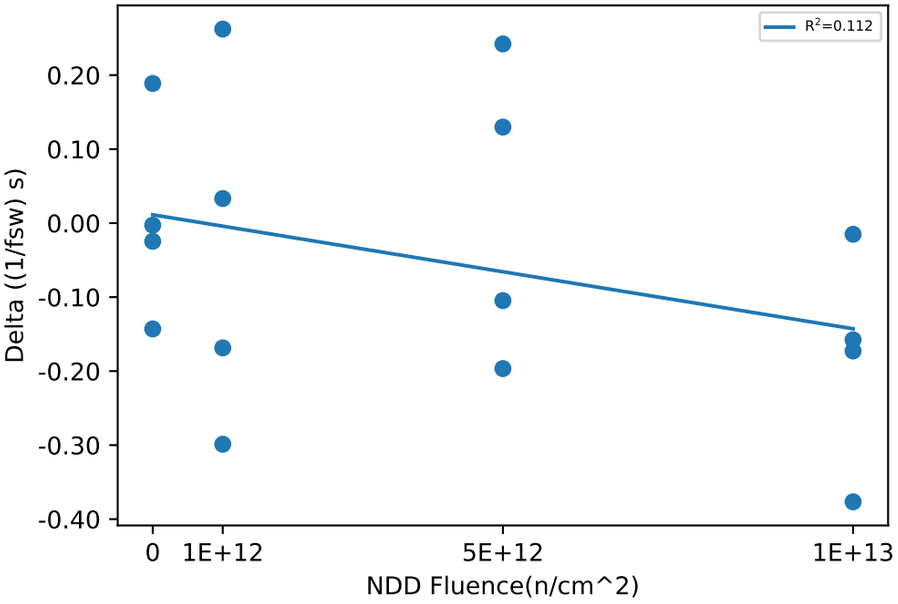
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9564	2.0831	2.2012	0.11427	2.0644	2.1243	2.2715	0.098716	-0.0836	0.041275	0.1337	0.091269
1e+12	1.9527	2.1348	2.2247	0.12377	1.9664	2.0872	2.2246	0.11613	-0.2583	-0.047675	0.2719	0.22818
5e+12	1.9627	2.0756	2.2015	0.097782	1.976	2.1347	2.3122	0.17488	-0.0751	0.0591	0.2424	0.13381
1e+13	1.9009	2.1486	2.3683	0.22663	1.8549	2.0584	2.1911	0.14322	-0.2195	-0.090175	0.1952	0.19192

Device Test: 20.174 FREQ|DETECTION/RT/14/14/0/0/5/1MHz//@T_INT_CLK_DET

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



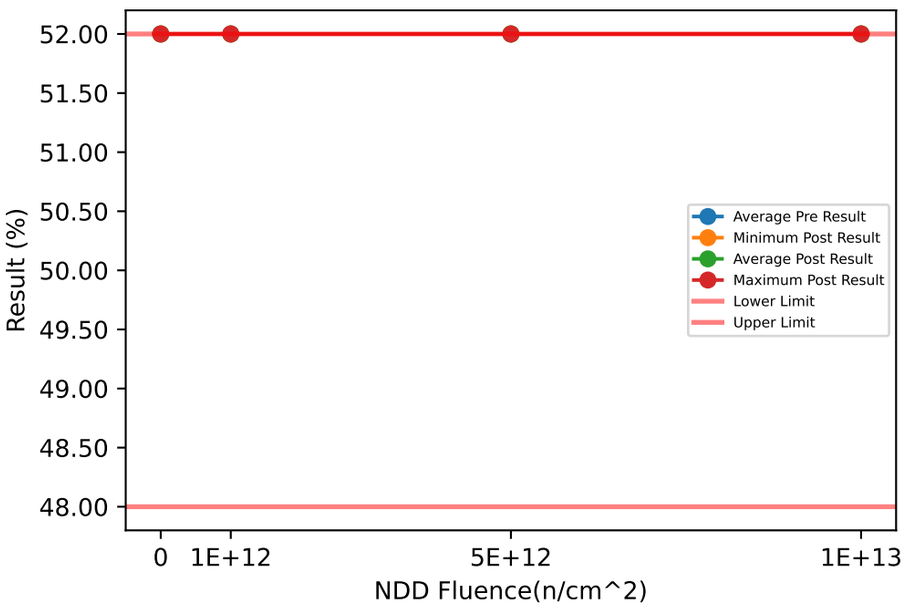
Test Results (Upper Limit = 5.0 ((1/fsw) s))

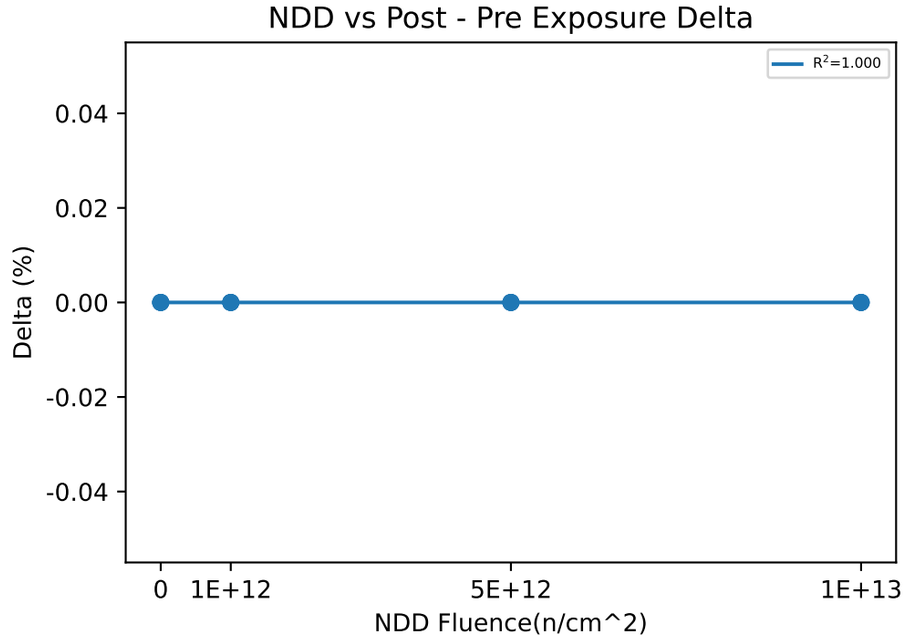
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.9981	2.1868	0.1887
466	1e+12	NDD	2.0103	2.0435	0.0332
762	0	CORRELATION	2.1988	2.196	-0.0028
769	1e+12	NDD	2.3311	2.0323	-0.2988
887	1e+12	NDD	2.168	1.9994	-0.1686
891	0	CORRELATION	2.021	1.9964	-0.0246
927	1e+12	NDD	2.0725	2.3347	0.2622
967	5e+12	NDD	2.1143	2.0096	-0.1047
1204	1e+13	NDD	2.1061	1.9333	-0.1728
1284	1e+13	NDD	1.999	1.9839	-0.0151
1292	5e+12	NDD	2.143	1.9464	-0.1966
1364	1e+13	NDD	2.2744	2.1167	-0.1577
1383	5e+12	NDD	2.0909	2.2207	0.1298
1388	5e+12	NDD	1.9655	2.2076	0.2421
1427	1e+13	NDD	2.3072	1.9306	-0.3766
1666	0	CORRELATION	2.158	2.015	-0.143

Test Statistics ((1/fsw) s)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9981	2.094	2.1988	0.099339	1.9964	2.0985	2.196	0.10755	-0.143	0.004575	0.1887	0.13734
1e+12	2.0103	2.1455	2.3311	0.13972	1.9994	2.1025	2.3347	0.15594	-0.2988	-0.043	0.2622	0.24506
5e+12	1.9655	2.0784	2.143	0.07824	1.9464	2.0961	2.2207	0.13886	-0.1966	0.01765	0.2421	0.20316
1e+13	1.999	2.1717	2.3072	0.14496	1.9306	1.9911	2.1167	0.087232	-0.3766	-0.18055	-0.0151	0.14876

Device Test: 20.18 PF|DCL_52/SYNC/4.5/4.5/0/0/4.5/100kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

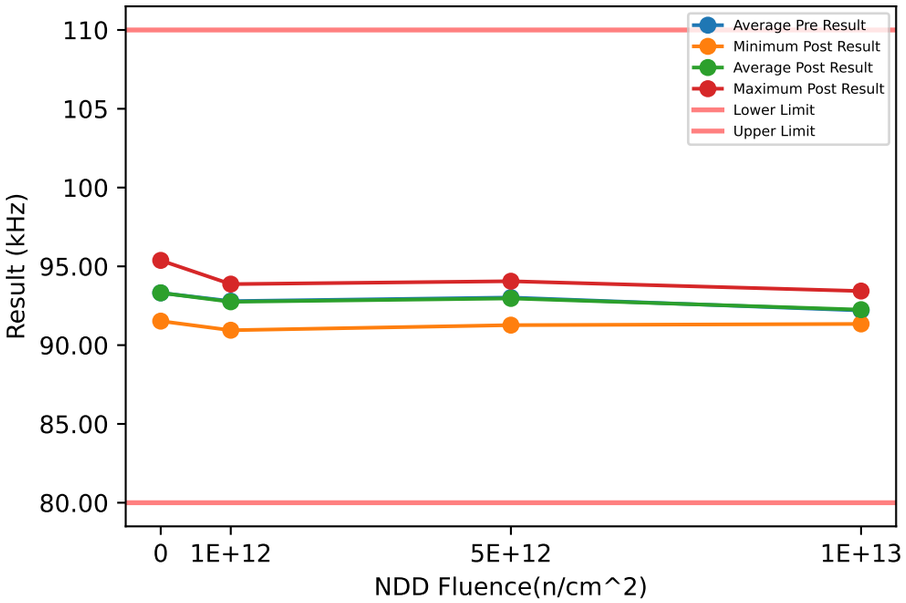
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

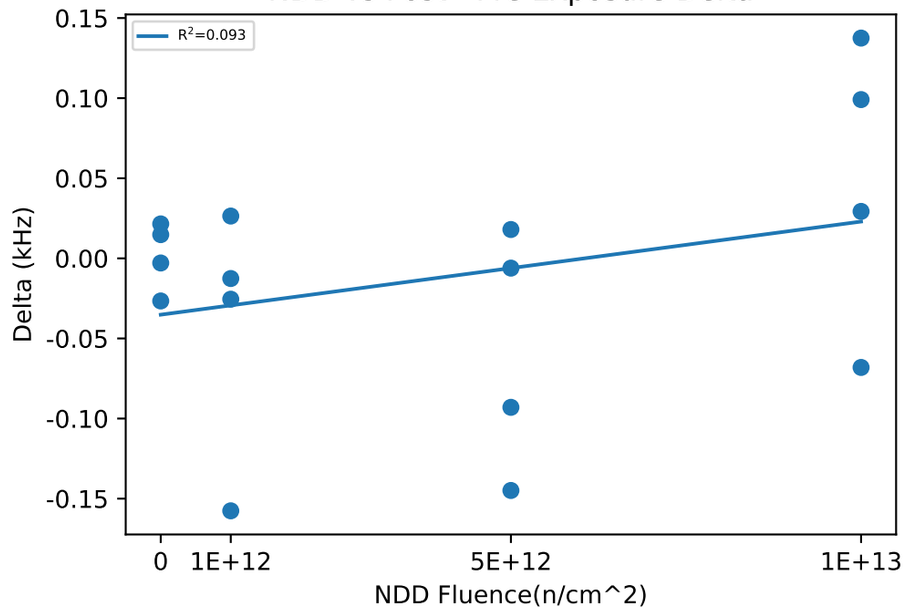
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.19 LEVEL|FREQ/RT/5/5/0/0/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

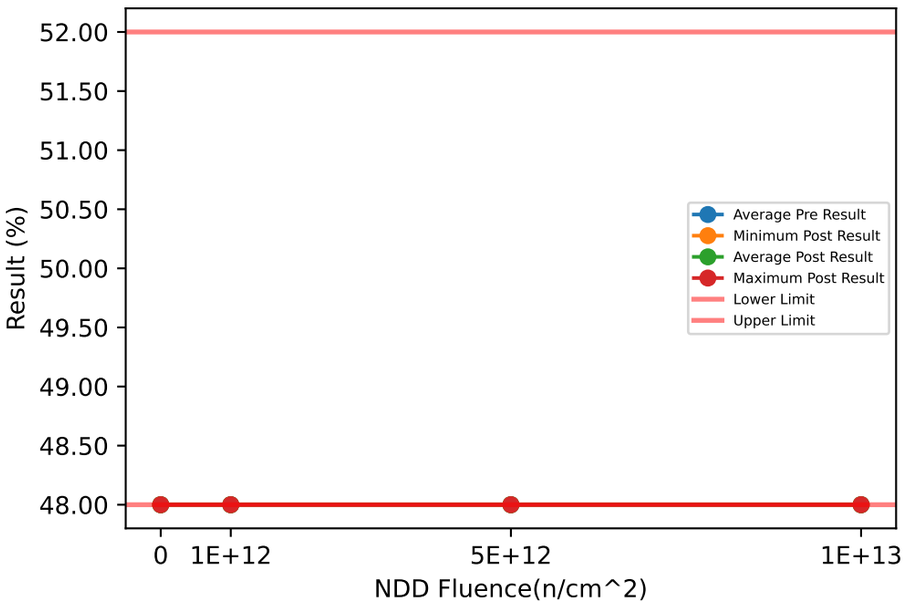
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	92.752	92.749	-0.0029
466	1e+12	NDD	93.595	93.583	-0.0126
762	0	CORRELATION	91.503	91.524	0.0215
769	1e+12	NDD	92.626	92.6	-0.0255
887	1e+12	NDD	94.031	93.873	-0.1576
891	0	CORRELATION	95.363	95.378	0.0148
927	1e+12	NDD	90.919	90.946	0.0264
967	5e+12	NDD	94.038	94.056	0.018
1204	1e+13	NDD	92.509	92.441	-0.0681
1284	1e+13	NDD	93.295	93.433	0.1375
1292	5e+12	NDD	92.862	92.717	-0.1449
1364	1e+13	NDD	91.246	91.345	0.0991
1383	5e+12	NDD	93.822	93.816	-0.0061
1388	5e+12	NDD	91.362	91.269	-0.093
1427	1e+13	NDD	91.754	91.783	0.0293
1666	0	CORRELATION	93.645	93.619	-0.0266

Test Statistics (kHz)

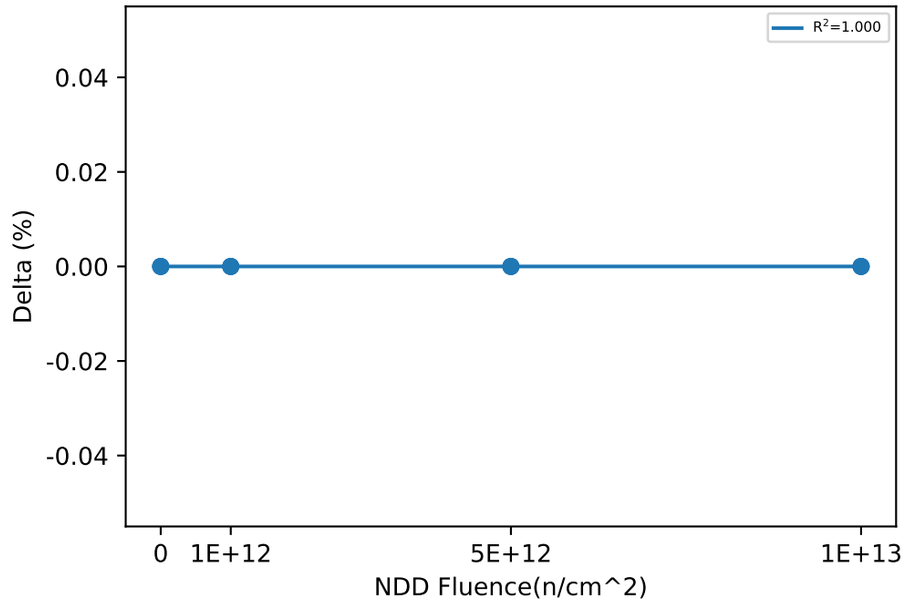
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.503	93.316	95.363	1.6231	91.524	93.317	95.378	1.62	-0.0266	0.0017	0.0215	0.021492
1e+12	90.919	92.793	94.031	1.38	90.946	92.75	93.873	1.3206	-0.1576	-0.042325	0.0264	0.079954
5e+12	91.362	93.021	94.038	1.2184	91.269	92.965	94.056	1.2718	-0.1449	-0.0565	0.018	0.075801
1e+13	91.246	92.201	93.295	0.895	91.345	92.25	93.433	0.90756	-0.0681	0.04945	0.1375	0.090262

Device Test: 20.21 PF|DCL_48/SYNC/5/5/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

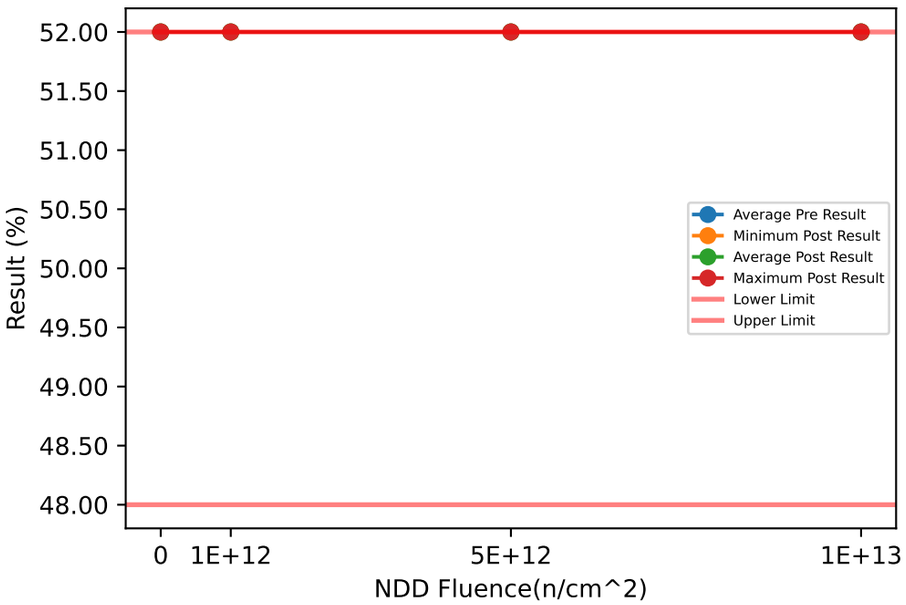
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

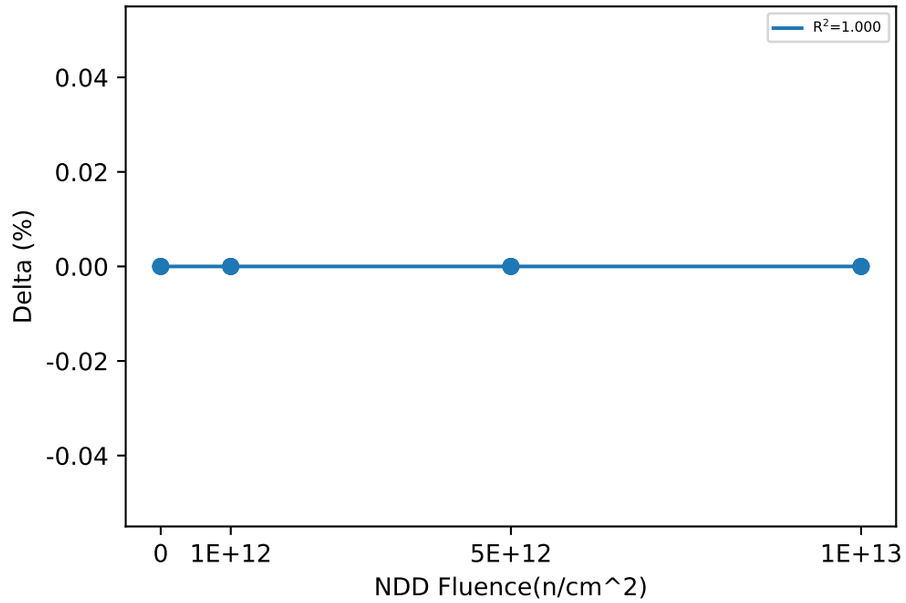
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.22 PF|DCL_52/SYNC/5/5/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

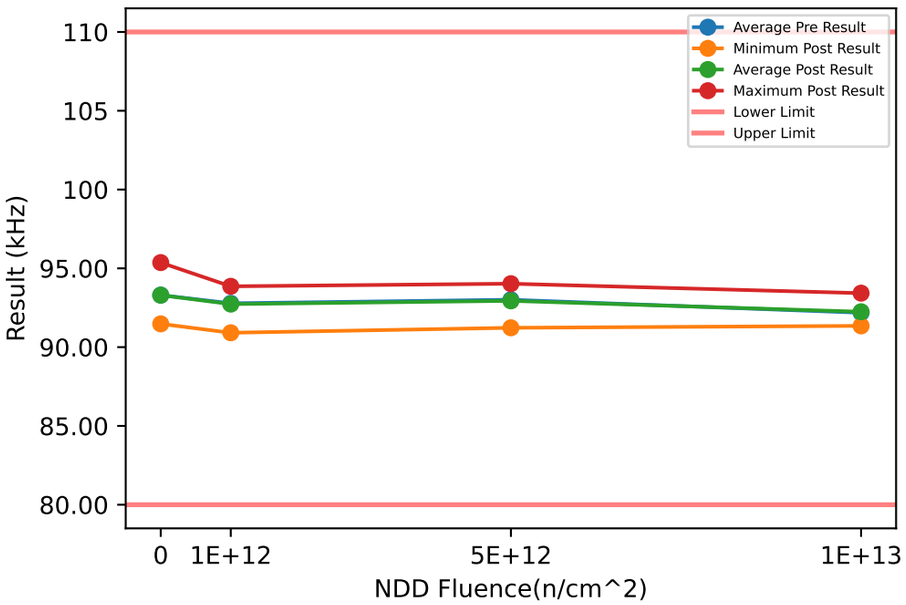
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

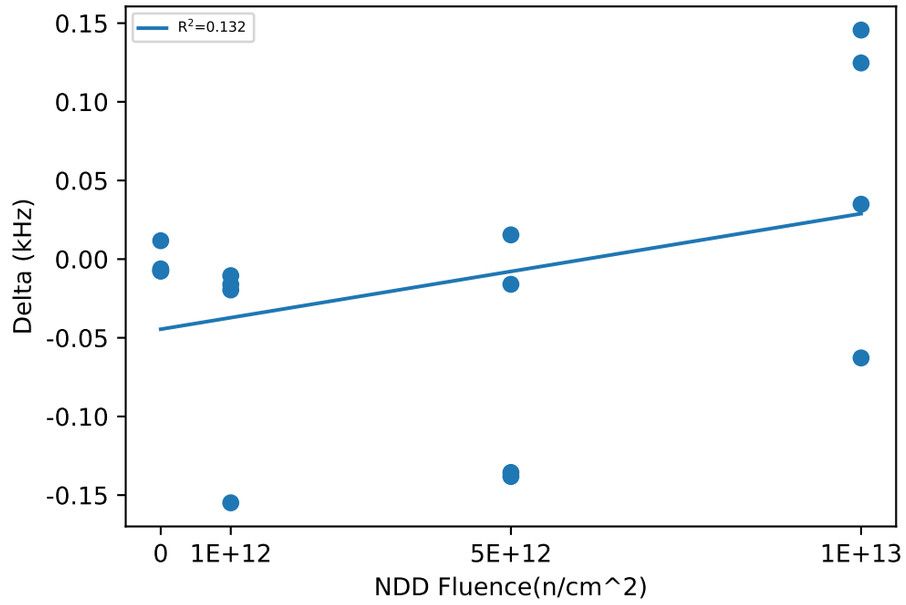
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.23 LEVEL|FREQ/RT/12/12/0/0/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

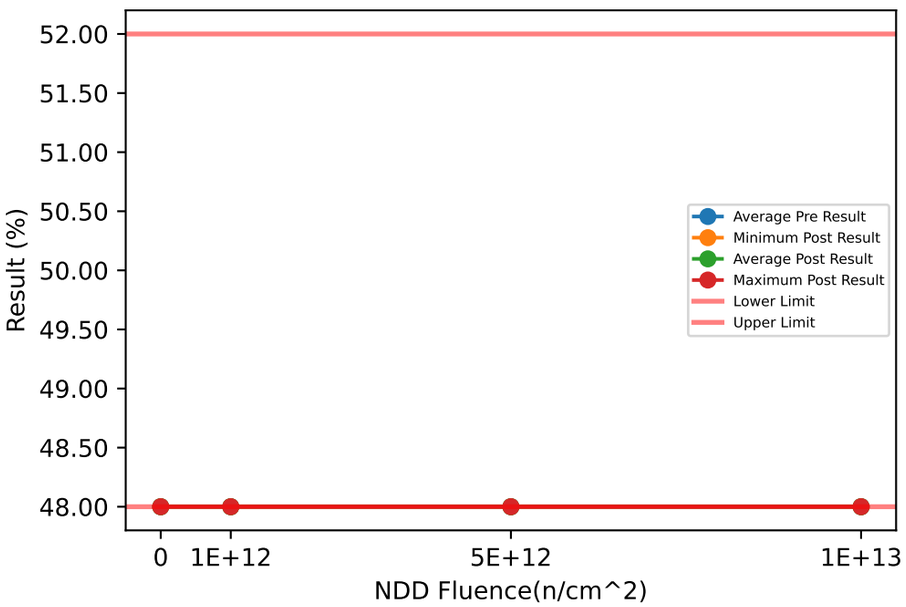
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	92.753	92.745	-0.0075
466	1e+12	NDD	93.578	93.562	-0.0161
762	0	CORRELATION	91.485	91.477	-0.0076
769	1e+12	NDD	92.607	92.588	-0.0196
887	1e+12	NDD	94.015	93.86	-0.1549
891	0	CORRELATION	95.354	95.365	0.0117
927	1e+12	NDD	90.922	90.912	-0.0105
967	5e+12	NDD	94.011	94.026	0.0154
1204	1e+13	NDD	92.497	92.434	-0.0628
1284	1e+13	NDD	93.28	93.426	0.1456
1292	5e+12	NDD	92.842	92.707	-0.1356
1364	1e+13	NDD	91.224	91.349	0.1247
1383	5e+12	NDD	93.807	93.791	-0.016
1388	5e+12	NDD	91.366	91.228	-0.1382
1427	1e+13	NDD	91.737	91.772	0.0349
1666	0	CORRELATION	93.611	93.605	-0.0062

Test Statistics (kHz)

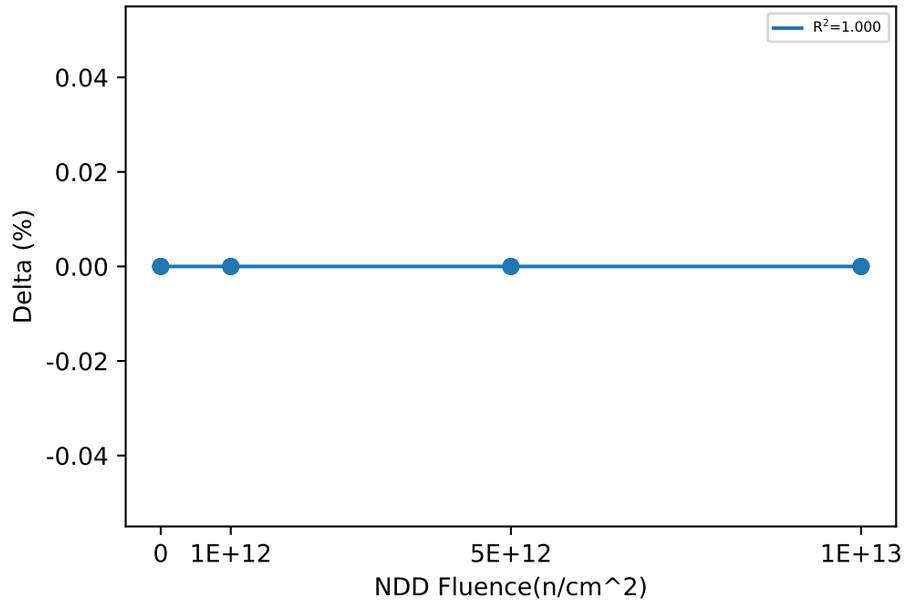
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.485	93.301	95.354	1.6237	91.477	93.298	95.365	1.6319	-0.0076	-0.0024	0.0117	0.0094216
1e+12	90.922	92.781	94.015	1.3714	90.912	92.73	93.86	1.3285	-0.1549	-0.050275	-0.0105	0.069851
5e+12	91.366	93.007	94.011	1.2067	91.228	92.938	94.026	1.2769	-0.1382	-0.0686	0.0154	0.079908
1e+13	91.224	92.185	93.28	0.89833	91.349	92.245	93.426	0.90505	-0.0628	0.0606	0.1456	0.095257

Device Test: 20.25 PF|DCL_48/SYNC/12/12/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



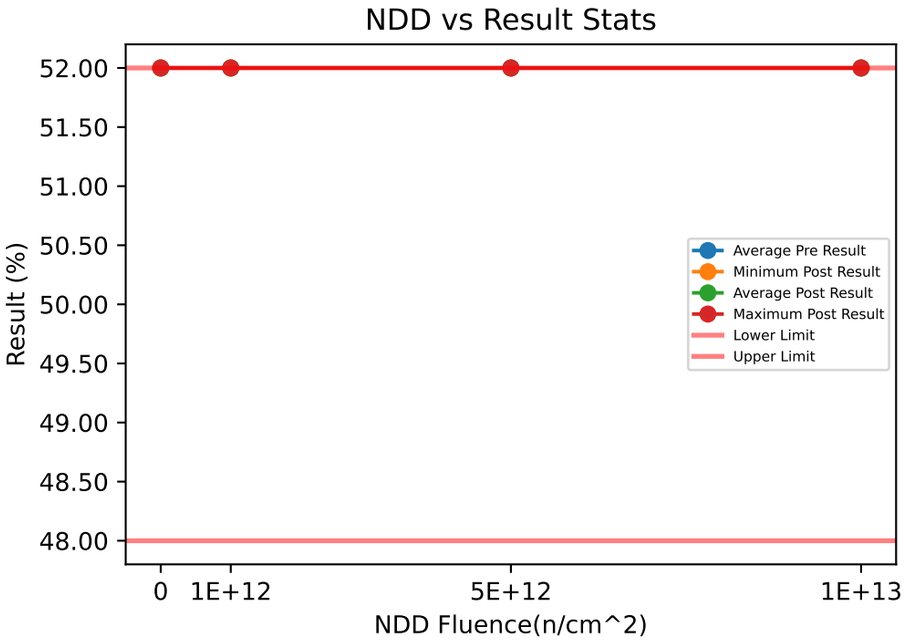
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

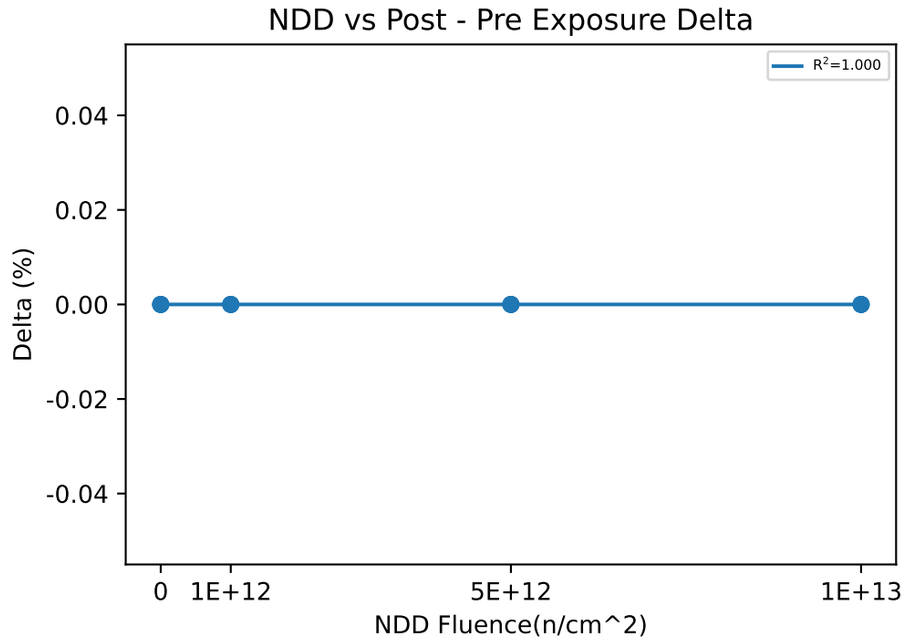
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.26 PF|DCL_52/SYNC/12/12/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

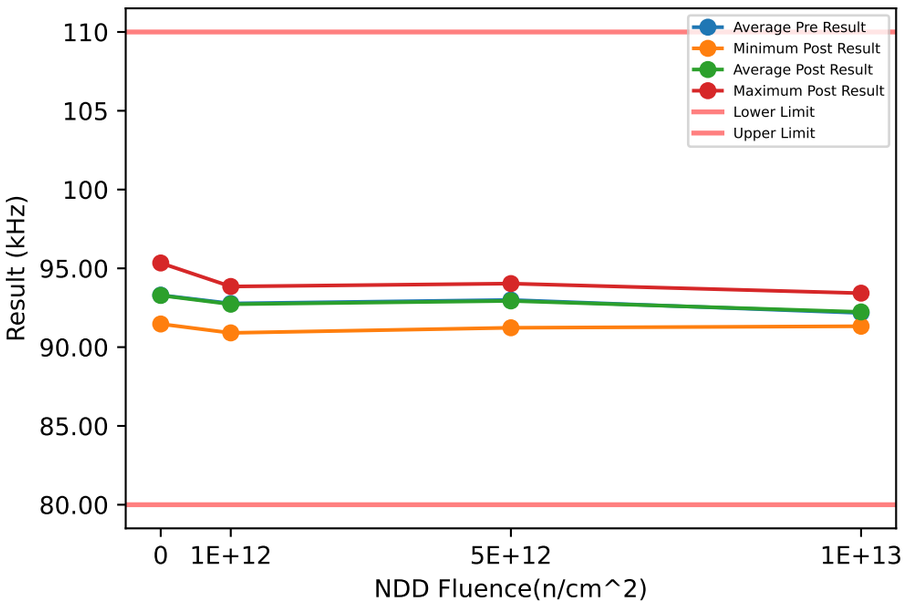
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

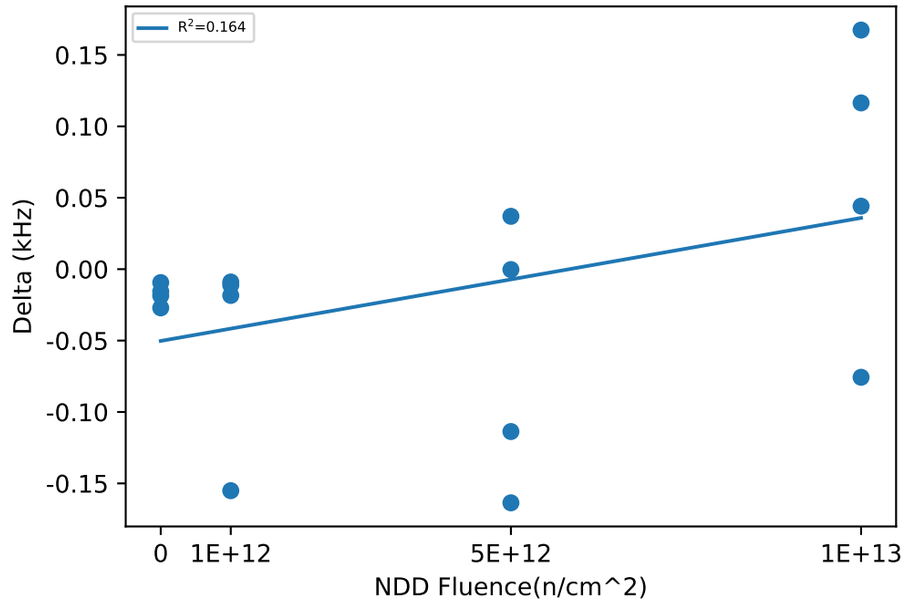
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.27 LEVEL|FREQ/RT/14/14/0/0/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

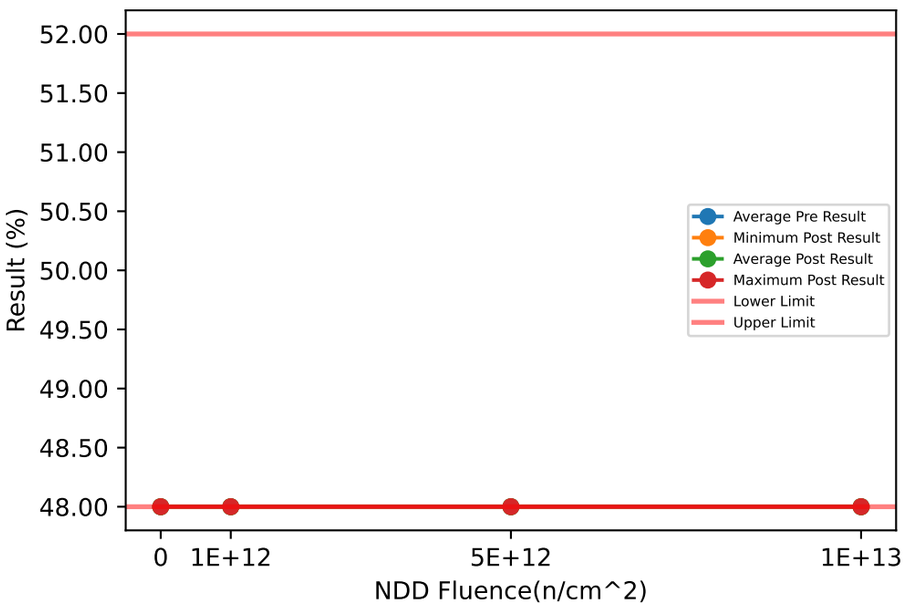
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	92.744	92.729	-0.0156
466	1e+12	NDD	93.581	93.57	-0.0112
762	0	CORRELATION	91.478	91.469	-0.0094
769	1e+12	NDD	92.589	92.571	-0.0184
887	1e+12	NDD	94.004	93.849	-0.1551
891	0	CORRELATION	95.359	95.34	-0.0186
927	1e+12	NDD	90.913	90.904	-0.009
967	5e+12	NDD	93.996	94.033	0.037
1204	1e+13	NDD	92.499	92.423	-0.0757
1284	1e+13	NDD	93.258	93.425	0.1674
1292	5e+12	NDD	92.84	92.676	-0.1636
1364	1e+13	NDD	91.209	91.325	0.1164
1383	5e+12	NDD	93.797	93.796	-0.0003
1388	5e+12	NDD	91.343	91.229	-0.1137
1427	1e+13	NDD	91.716	91.76	0.0441
1666	0	CORRELATION	93.616	93.588	-0.0271

Test Statistics (kHz)

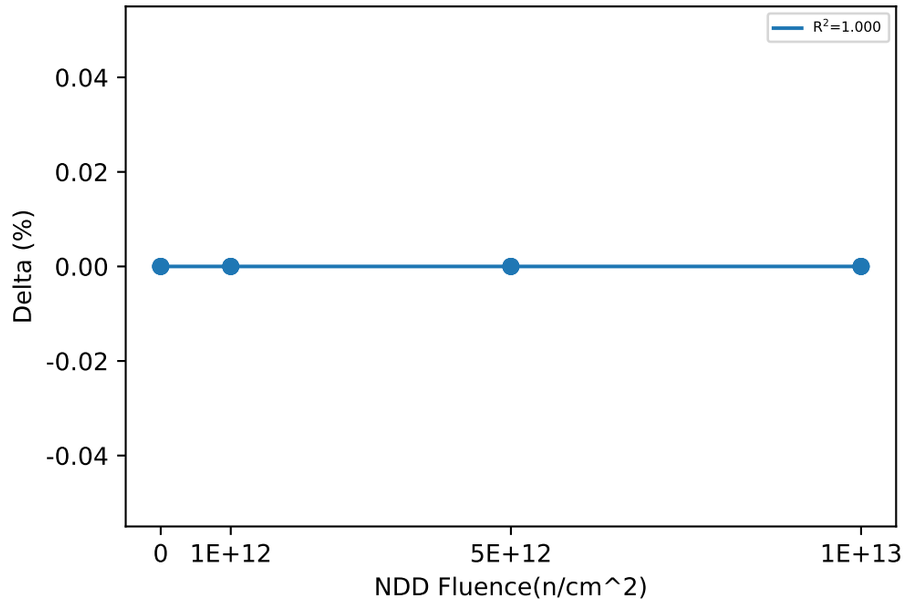
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.478	93.299	95.359	1.6295	91.469	93.282	95.34	1.6252	-0.0271	-0.017675	-0.0094	0.0073591
1e+12	90.913	92.772	94.004	1.3737	90.904	92.724	93.849	1.3312	-0.1551	-0.048425	-0.009	0.07123
5e+12	91.343	92.994	93.996	1.2109	91.229	92.934	94.033	1.2813	-0.1636	-0.06015	0.037	0.094145
1e+13	91.209	92.17	93.258	0.89837	91.325	92.233	93.425	0.91377	-0.0757	0.06305	0.1674	0.10543

Device Test: 20.29 PF|DCL_48/SYNC/14/14/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



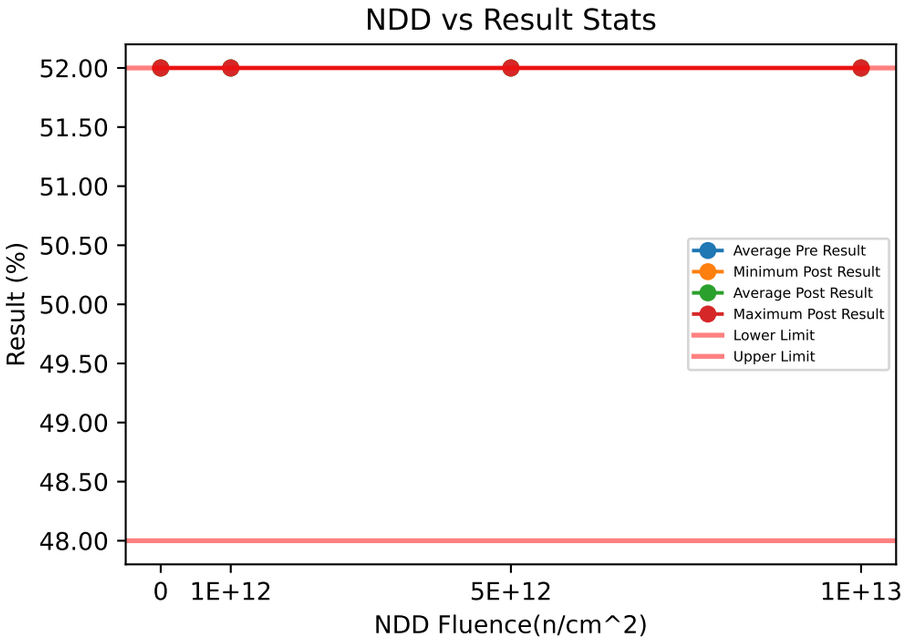
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

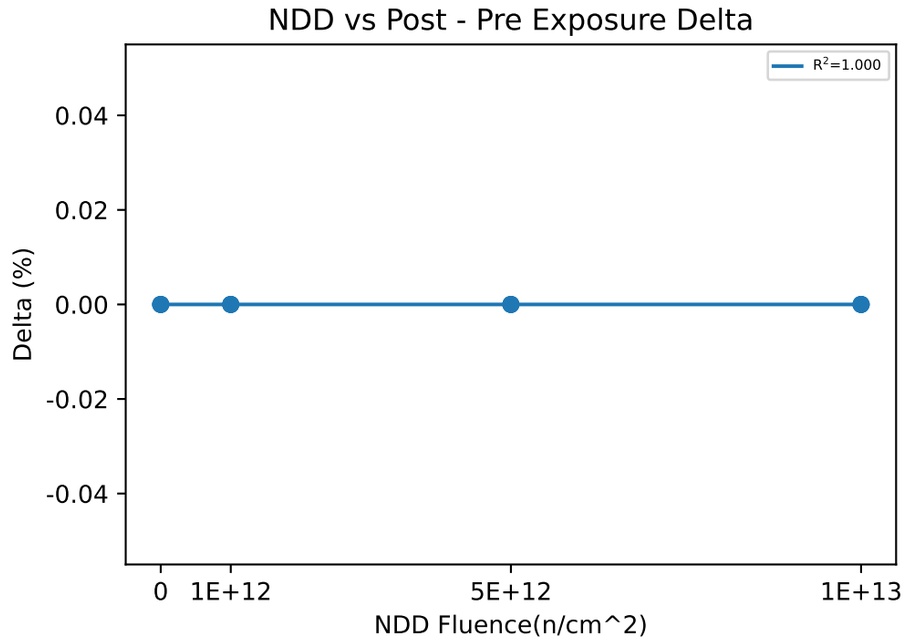
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.30 PF|DCL_52/SYNC/14/14/0/0/5/100kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

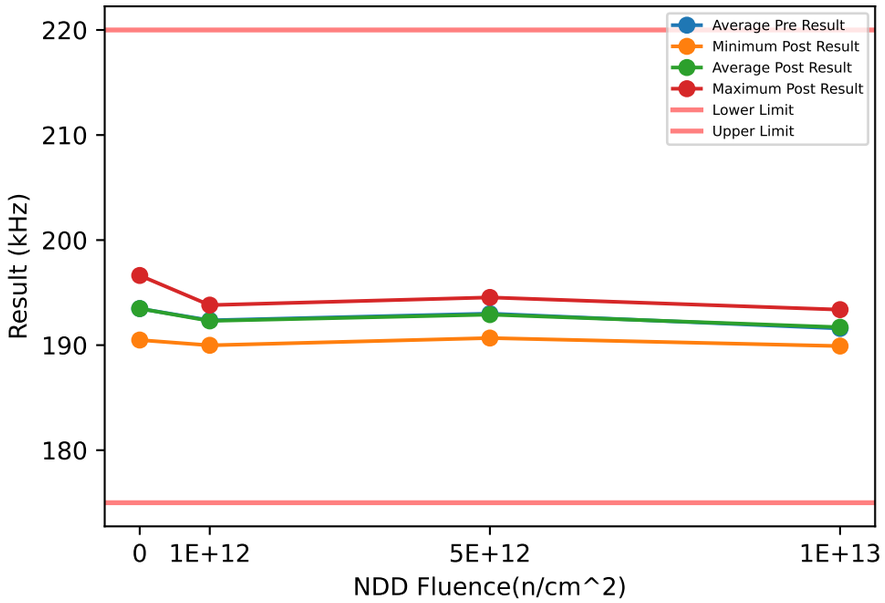
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

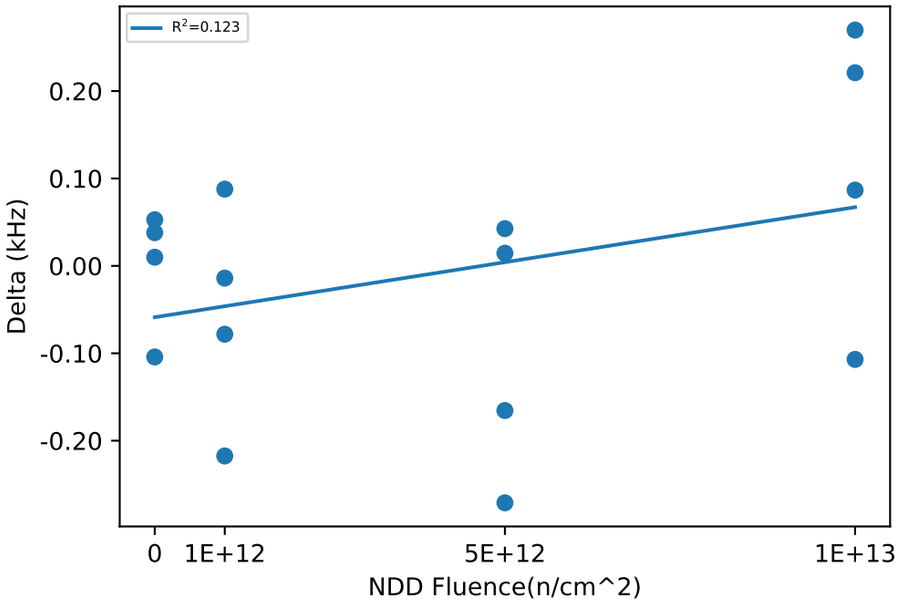
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.31 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

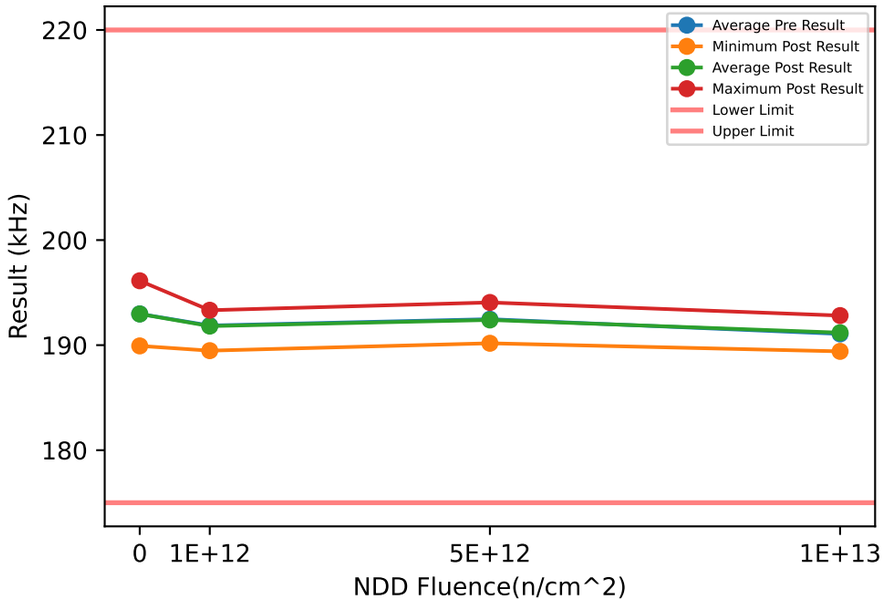
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.97	192.86	-0.1042
466	1e+12	NDD	193.28	193.27	-0.014
762	0	CORRELATION	190.48	190.49	0.0099
769	1e+12	NDD	192.08	192.17	0.0878
887	1e+12	NDD	194.03	193.81	-0.2175
891	0	CORRELATION	196.59	196.63	0.038
927	1e+12	NDD	190.06	189.98	-0.0782
967	5e+12	NDD	194.5	194.54	0.0426
1204	1e+13	NDD	192.49	192.38	-0.107
1284	1e+13	NDD	193.11	193.38	0.2698
1292	5e+12	NDD	192.64	192.47	-0.1655
1364	1e+13	NDD	189.69	189.91	0.221
1383	5e+12	NDD	193.92	193.93	0.0145
1388	5e+12	NDD	190.95	190.68	-0.2711
1427	1e+13	NDD	191.06	191.14	0.0867
1666	0	CORRELATION	193.88	193.94	0.0528

Test Statistics (kHz)

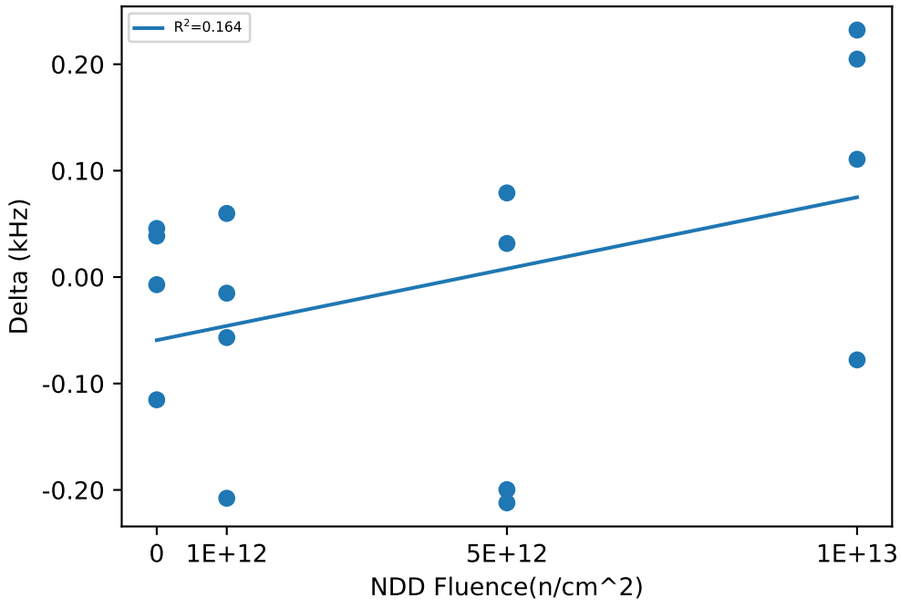
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	190.48	193.48	196.59	2.5269	190.49	193.48	196.63	2.5494	-0.1042	-0.000875	0.0528	0.071144
1e+12	190.06	192.36	194.03	1.7314	189.98	192.31	193.81	1.6934	-0.2175	-0.055475	0.0878	0.12782
5e+12	190.95	193	194.5	1.5737	190.68	192.91	194.54	1.7208	-0.2711	-0.094875	0.0426	0.14934
1e+13	189.69	191.59	193.11	1.5288	189.91	191.7	193.38	1.5049	-0.107	0.11762	0.2698	0.16858

Device Test: 20.33 LEVEL|FREQ/RT/5/5/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

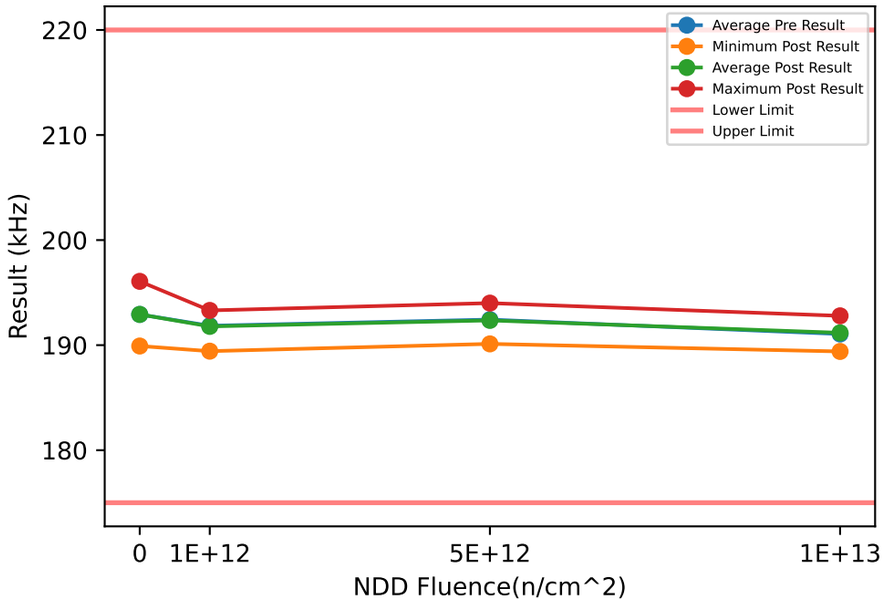
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.47	192.36	-0.1153
466	1e+12	NDD	192.82	192.81	-0.0151
762	0	CORRELATION	189.93	189.93	-0.0071
769	1e+12	NDD	191.58	191.64	0.0598
887	1e+12	NDD	193.53	193.32	-0.2078
891	0	CORRELATION	196.09	196.13	0.0386
927	1e+12	NDD	189.53	189.47	-0.0568
967	5e+12	NDD	193.98	194.06	0.0791
1204	1e+13	NDD	191.97	191.89	-0.0778
1284	1e+13	NDD	192.58	192.81	0.2321
1292	5e+12	NDD	192.13	191.92	-0.2121
1364	1e+13	NDD	189.2	189.41	0.2048
1383	5e+12	NDD	193.39	193.42	0.0316
1388	5e+12	NDD	190.38	190.18	-0.1997
1427	1e+13	NDD	190.52	190.63	0.1107
1666	0	CORRELATION	193.4	193.45	0.0457

Test Statistics (kHz)

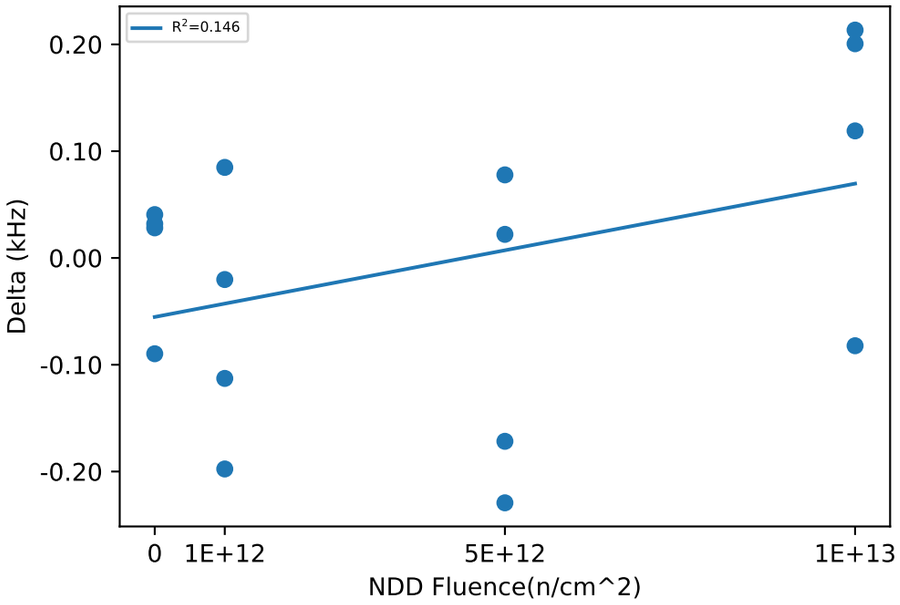
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.93	192.98	196.09	2.5412	189.93	192.97	196.13	2.5708	-0.1153	-0.009525	0.0457	0.074297
1e+12	189.53	191.87	193.53	1.7524	189.47	191.81	193.32	1.7091	-0.2078	-0.054975	0.0598	0.11273
5e+12	190.38	192.47	193.98	1.5945	190.18	192.4	194.06	1.7295	-0.2121	-0.075275	0.0791	0.15216
1e+13	189.2	191.07	192.58	1.5146	189.41	191.19	192.81	1.4853	-0.0778	0.11745	0.2321	0.14017

Device Test: 20.35 LEVEL|FREQ/RT/12/12/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

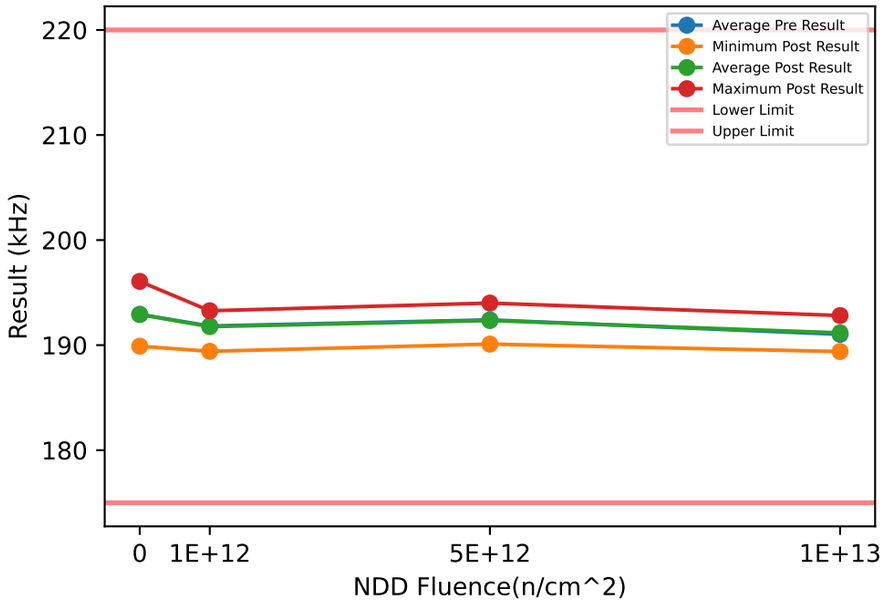
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.42	192.33	-0.0897
466	1e+12	NDD	192.81	192.79	-0.0202
762	0	CORRELATION	189.88	189.92	0.032
769	1e+12	NDD	191.53	191.62	0.0848
887	1e+12	NDD	193.5	193.3	-0.1976
891	0	CORRELATION	196.04	196.07	0.0282
927	1e+12	NDD	189.54	189.43	-0.1128
967	5e+12	NDD	193.92	194	0.0778
1204	1e+13	NDD	191.97	191.89	-0.0822
1284	1e+13	NDD	192.58	192.79	0.2134
1292	5e+12	NDD	192.08	191.91	-0.1717
1364	1e+13	NDD	189.2	189.4	0.2006
1383	5e+12	NDD	193.37	193.39	0.0221
1388	5e+12	NDD	190.35	190.12	-0.2293
1427	1e+13	NDD	190.5	190.62	0.119
1666	0	CORRELATION	193.34	193.38	0.0406

Test Statistics (kHz)

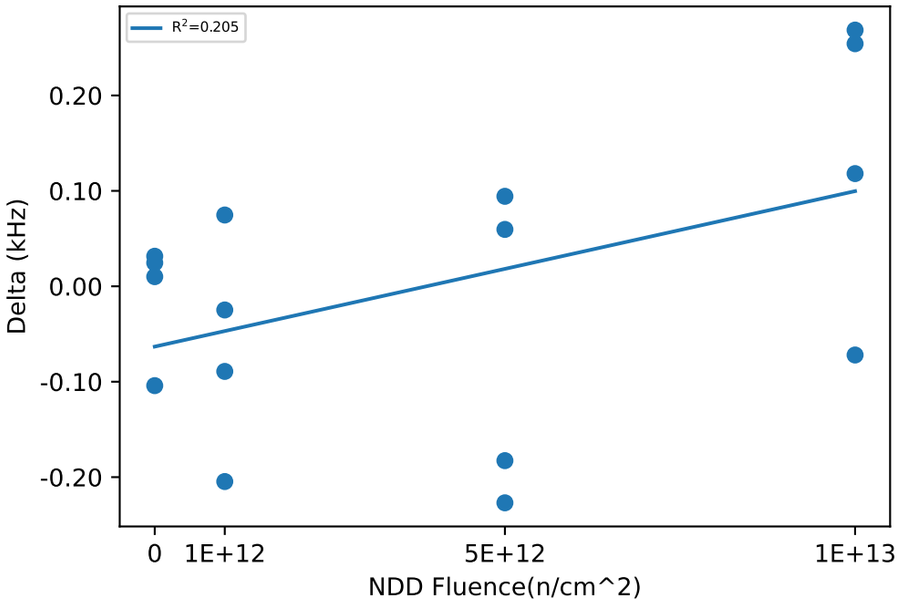
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.88	192.92	196.04	2.5429	189.92	192.92	196.07	2.5505	-0.0897	0.002775	0.0406	0.061868
1e+12	189.54	191.85	193.5	1.7401	189.43	191.78	193.3	1.7225	-0.1976	-0.06145	0.0848	0.12147
5e+12	190.35	192.43	193.92	1.5876	190.12	192.35	194	1.7296	-0.2293	-0.075275	0.0778	0.14825
1e+13	189.2	191.06	192.58	1.5171	189.4	191.17	192.79	1.4807	-0.0822	0.1127	0.2134	0.13649

Device Test: 20.37 LEVEL|FREQ/RT/14/14/0/0/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

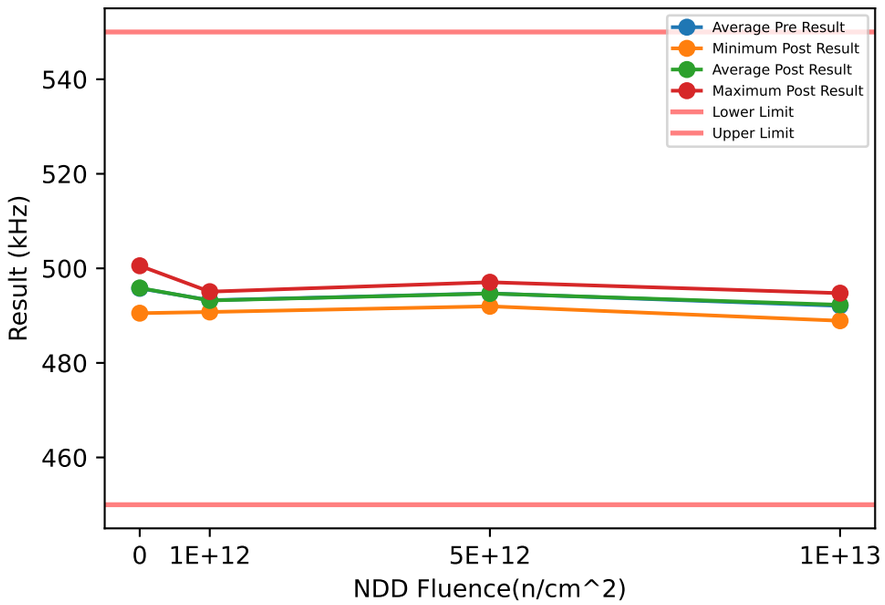
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.43	192.33	-0.1041
466	1e+12	NDD	192.78	192.76	-0.0248
762	0	CORRELATION	189.87	189.9	0.0315
769	1e+12	NDD	191.53	191.6	0.0747
887	1e+12	NDD	193.47	193.27	-0.2046
891	0	CORRELATION	196.04	196.07	0.0246
927	1e+12	NDD	189.5	189.41	-0.0892
967	5e+12	NDD	193.91	194	0.0943
1204	1e+13	NDD	191.94	191.87	-0.072
1284	1e+13	NDD	192.55	192.82	0.2685
1292	5e+12	NDD	192.05	191.87	-0.1827
1364	1e+13	NDD	189.14	189.39	0.2542
1383	5e+12	NDD	193.33	193.39	0.0596
1388	5e+12	NDD	190.33	190.1	-0.2269
1427	1e+13	NDD	190.49	190.61	0.1181
1666	0	CORRELATION	193.37	193.38	0.0101

Test Statistics (kHz)

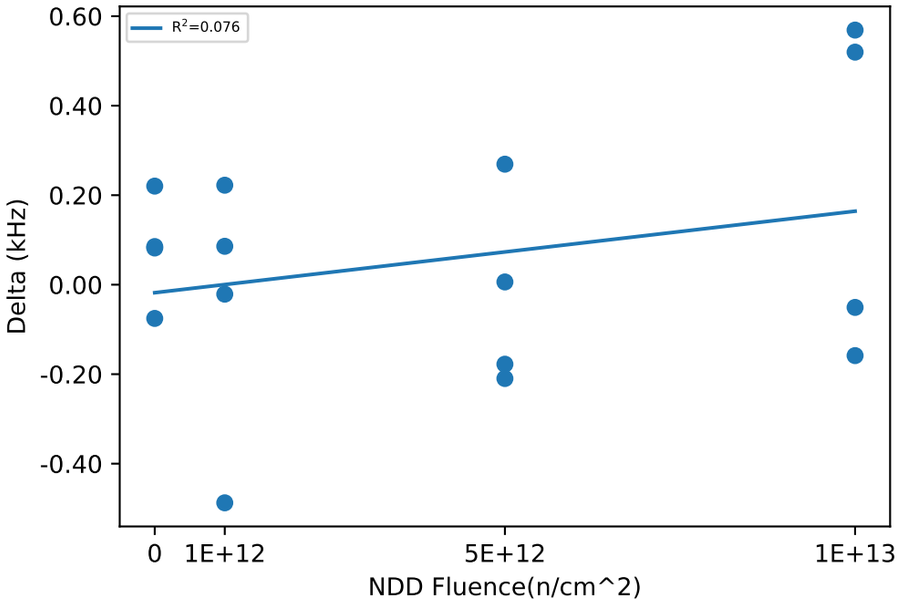
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.87	192.93	196.04	2.5507	189.9	192.92	196.07	2.5562	-0.1041	-0.009475	0.0315	0.063711
1e+12	189.5	191.82	193.47	1.7445	189.41	191.76	193.27	1.7144	-0.2046	-0.060975	0.0747	0.11711
5e+12	190.33	192.4	193.91	1.5882	190.1	192.34	194	1.7429	-0.2269	-0.063925	0.0943	0.16428
1e+13	189.14	191.03	192.55	1.5284	189.39	191.17	192.82	1.4922	-0.072	0.1422	0.2685	0.15807

Device Test: 20.39 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



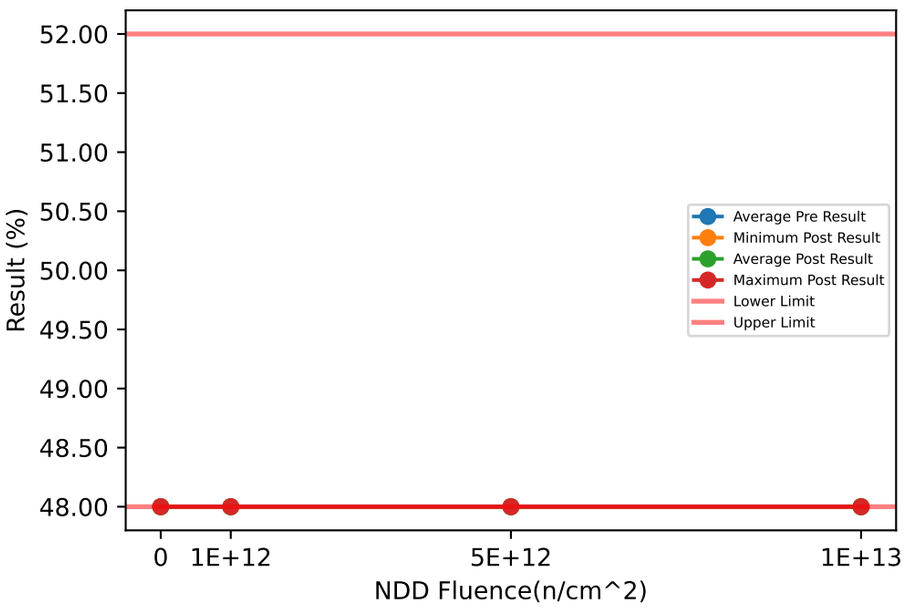
Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

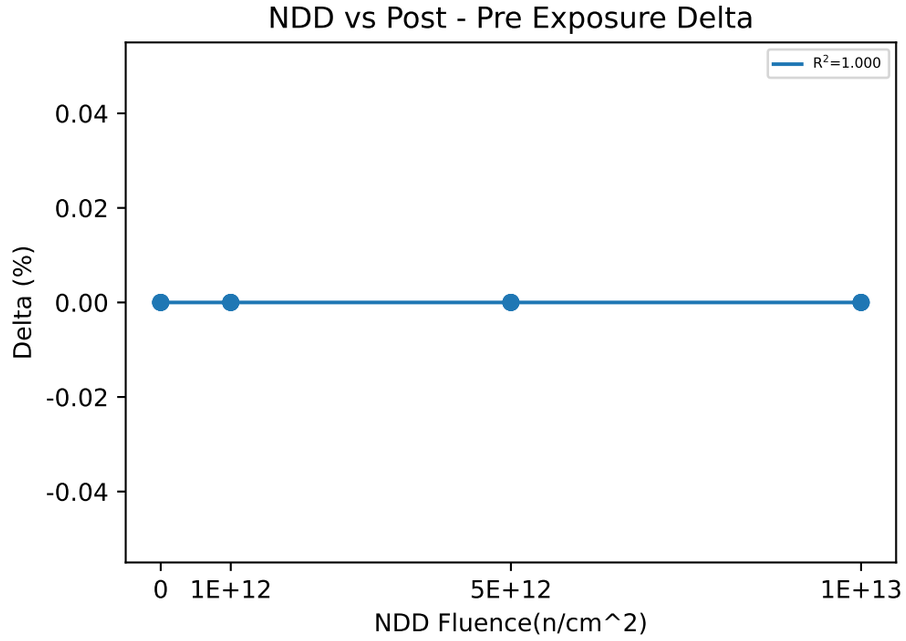
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	495.48	495.7	0.2203
466	1e+12	NDD	493.66	493.74	0.0858
762	0	CORRELATION	490.43	490.52	0.082
769	1e+12	NDD	493.25	493.23	-0.0212
887	1e+12	NDD	495.56	495.07	-0.4875
891	0	CORRELATION	500.46	500.55	0.0852
927	1e+12	NDD	490.55	490.77	0.2223
967	5e+12	NDD	497.27	497.06	-0.2097
1204	1e+13	NDD	494.8	494.75	-0.0508
1284	1e+13	NDD	493.36	493.93	0.569
1292	5e+12	NDD	493.76	493.59	-0.1777
1364	1e+13	NDD	488.4	488.92	0.5197
1383	5e+12	NDD	495.81	496.08	0.2693
1388	5e+12	NDD	491.96	491.97	0.0061
1427	1e+13	NDD	491.72	491.56	-0.1585
1666	0	CORRELATION	496.71	496.64	-0.0754

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	490.43	495.77	500.46	4.1423	490.52	495.85	500.55	4.1301	-0.0754	0.078025	0.2203	0.1209
1e+12	490.55	493.25	495.56	2.0652	490.77	493.2	495.07	1.7981	-0.4875	-0.05015	0.2223	0.30813
5e+12	491.96	494.7	497.27	2.3242	491.97	494.67	497.06	2.3216	-0.2097	-0.028	0.2693	0.21983
1e+13	488.4	492.07	494.8	2.7539	488.92	492.29	494.75	2.6246	-0.1585	0.21985	0.569	0.37781

Device Test: 20.41 PF|DCL_48/SYNC/4.5/4.5/0/0/4.5/500kHz//@DUTY_SYNC_EXT_DCL50





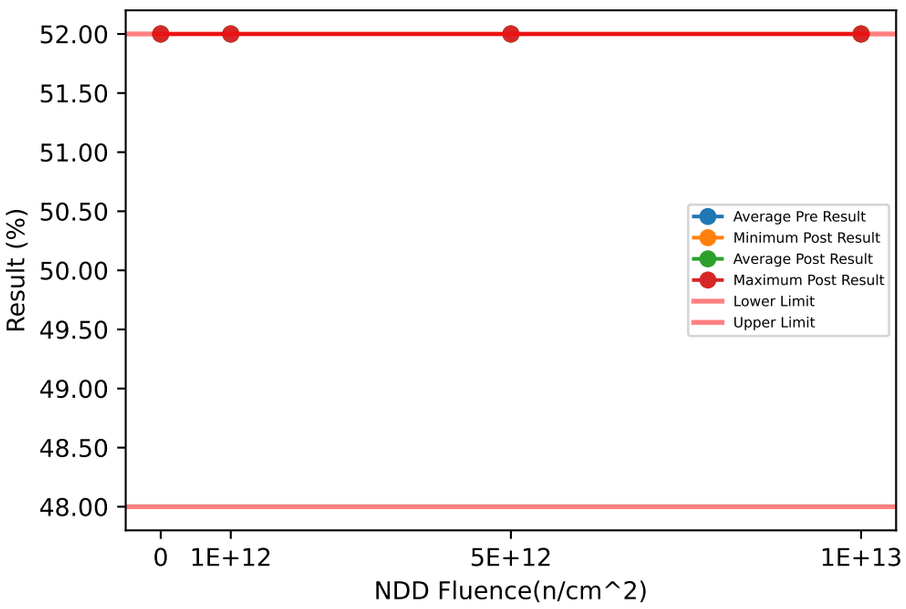
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

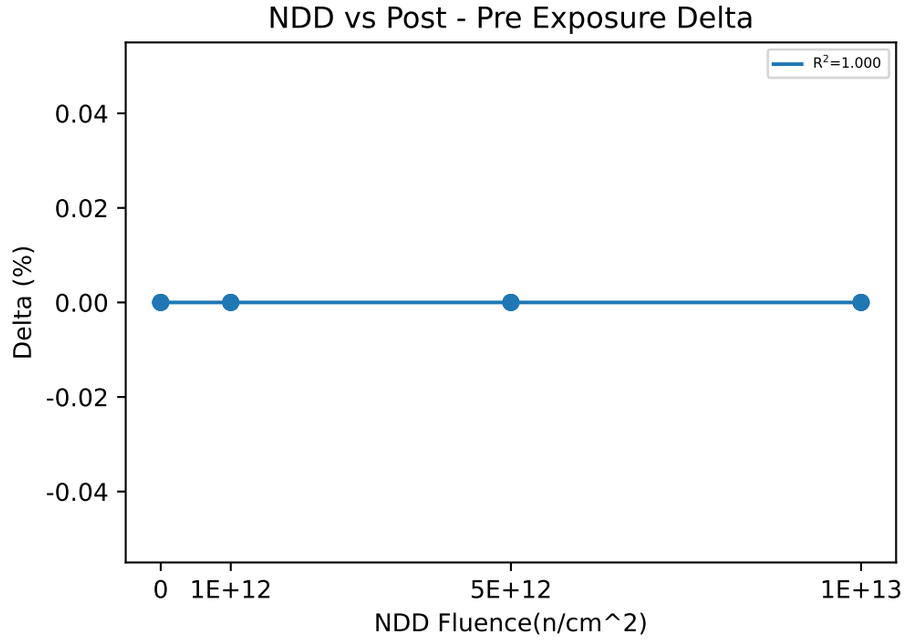
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.42 PF|DCL_52/SYNC/4.5/4.5/0/0/4.5/500kHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

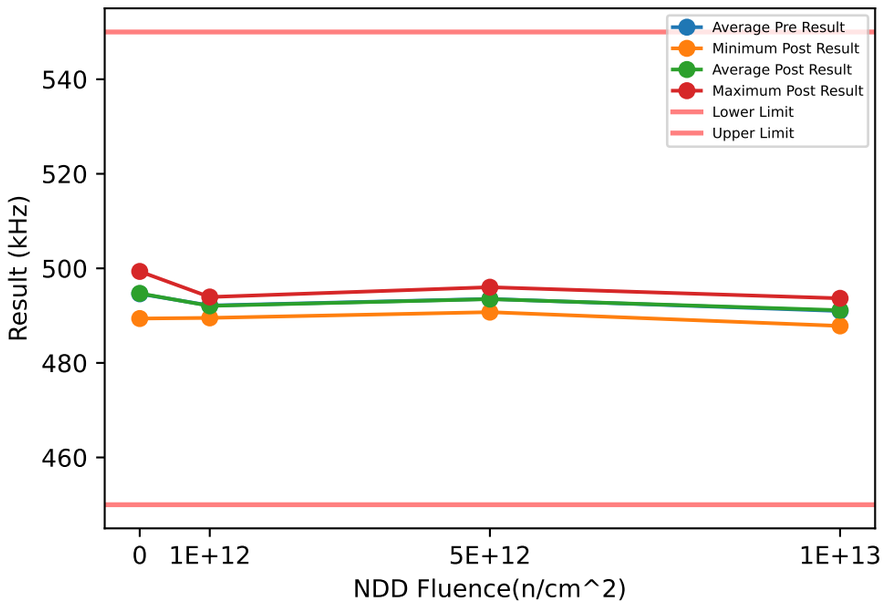
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

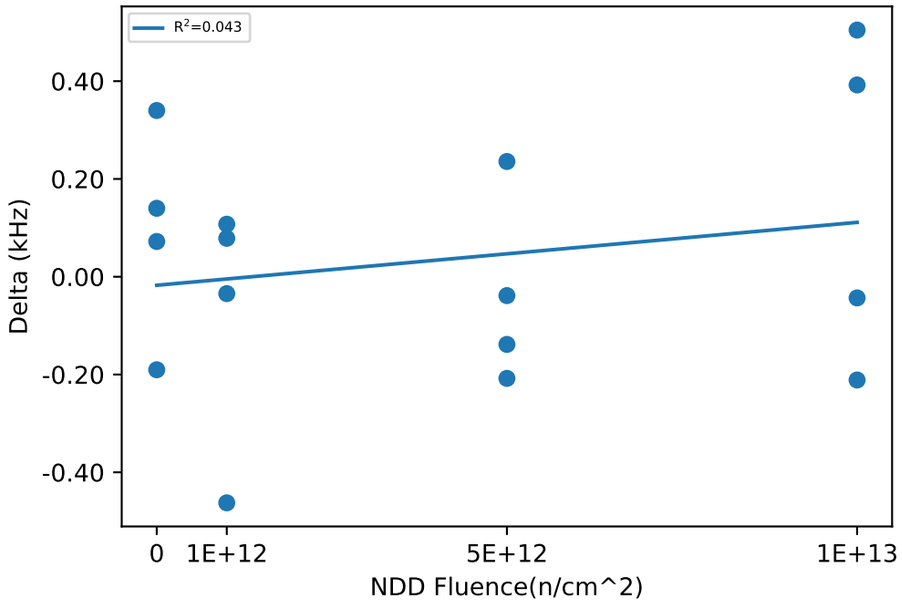
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.43 LEVEL|FREQ/RT/5/5/0/0/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

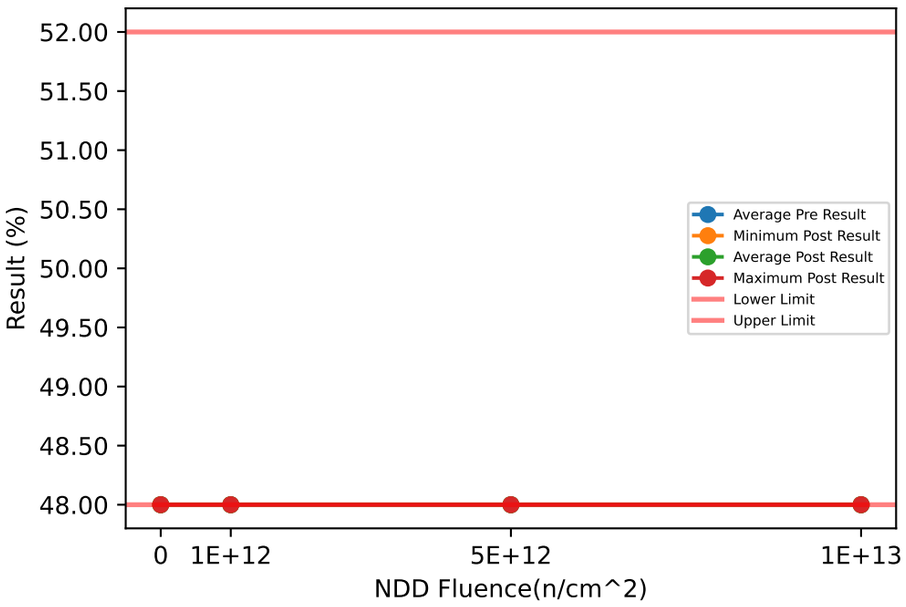
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	494.28	494.62	0.34
466	1e+12	NDD	492.63	492.71	0.0786
762	0	CORRELATION	489.24	489.38	0.14
769	1e+12	NDD	492.11	492.08	-0.0345
887	1e+12	NDD	494.4	493.94	-0.4624
891	0	CORRELATION	499.28	499.35	0.0721
927	1e+12	NDD	489.41	489.52	0.1075
967	5e+12	NDD	496.22	496.01	-0.2079
1204	1e+13	NDD	493.7	493.66	-0.0433
1284	1e+13	NDD	492.32	492.71	0.3923
1292	5e+12	NDD	492.5	492.36	-0.1384
1364	1e+13	NDD	487.32	487.82	0.5045
1383	5e+12	NDD	494.62	494.85	0.2357
1388	5e+12	NDD	490.77	490.74	-0.0386
1427	1e+13	NDD	490.57	490.36	-0.2112
1666	0	CORRELATION	495.64	495.45	-0.1903

Test Statistics (kHz)

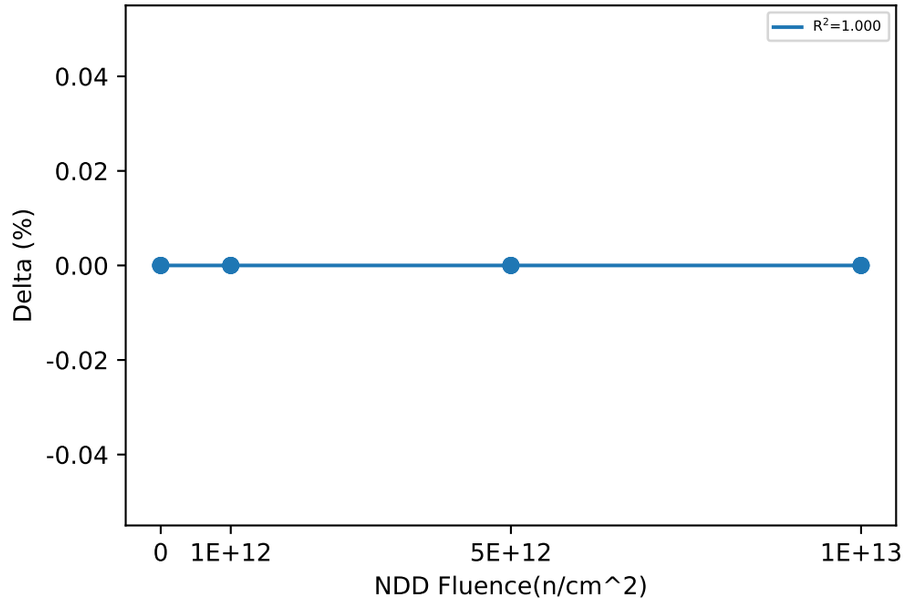
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	489.24	494.61	499.28	4.1532	489.38	494.7	499.35	4.1006	-0.1903	0.09045	0.34	0.219
1e+12	489.41	492.14	494.4	2.065	489.52	492.06	493.94	1.8622	-0.4624	-0.0777	0.1075	0.26368
5e+12	490.77	493.53	496.22	2.3842	490.74	493.49	496.01	2.3847	-0.2079	-0.0373	0.2357	0.19481
1e+13	487.32	490.98	493.7	2.7565	487.82	491.14	493.66	2.6105	-0.2112	0.16057	0.5045	0.34242

Device Test: 20.45 PF|DCL_48/SYNC/5/5/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

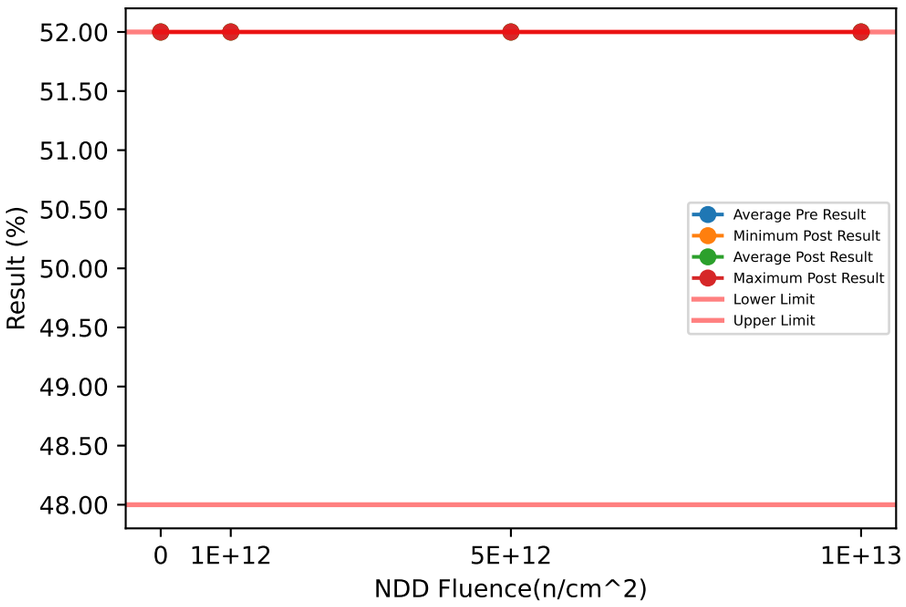
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

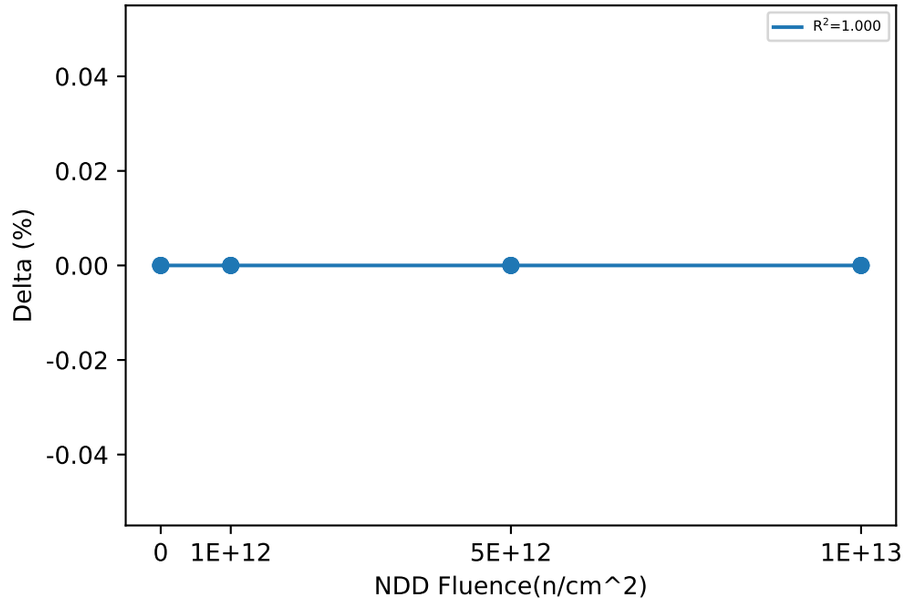
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.46 PF|DCL_52/SYNC/5/5/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

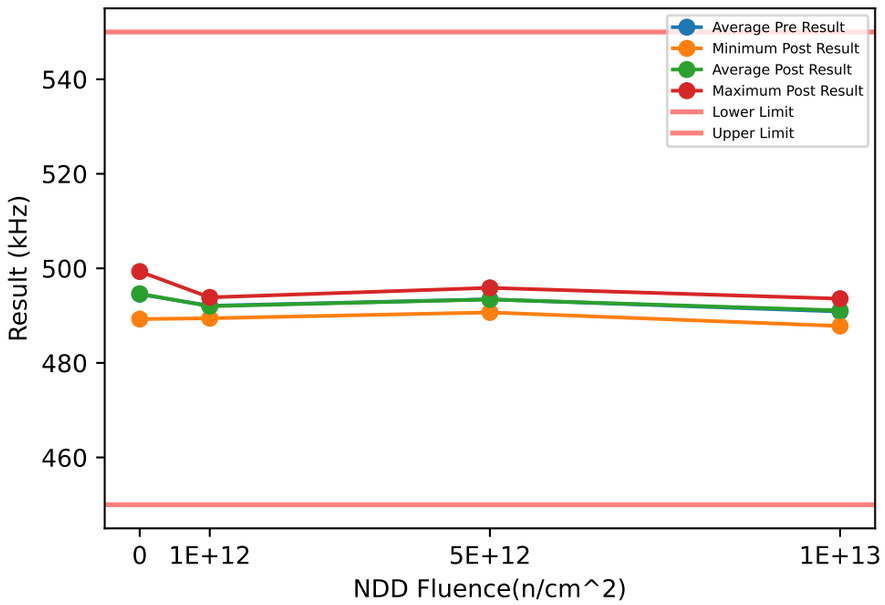
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

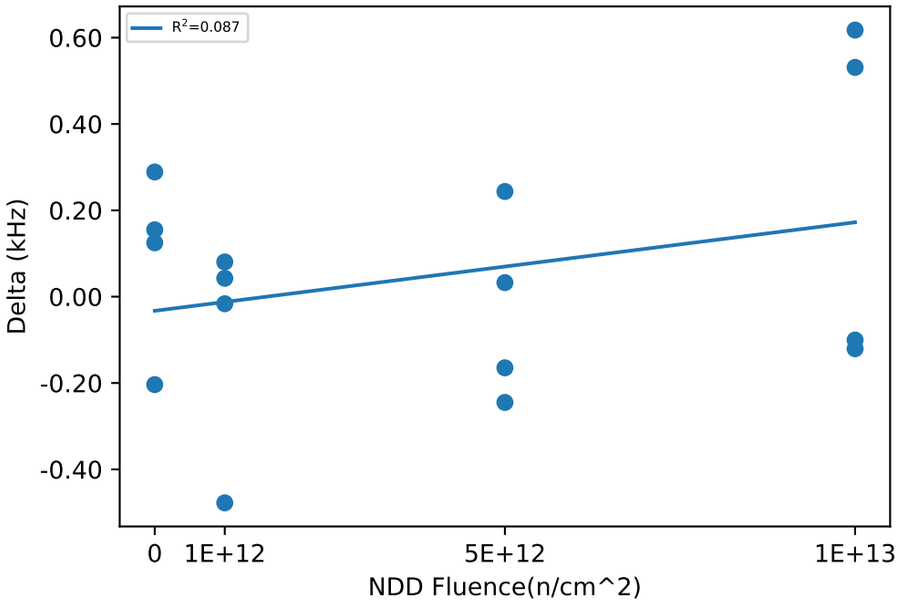
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.47 LEVEL|FREQ/RT/12/12/0/0/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

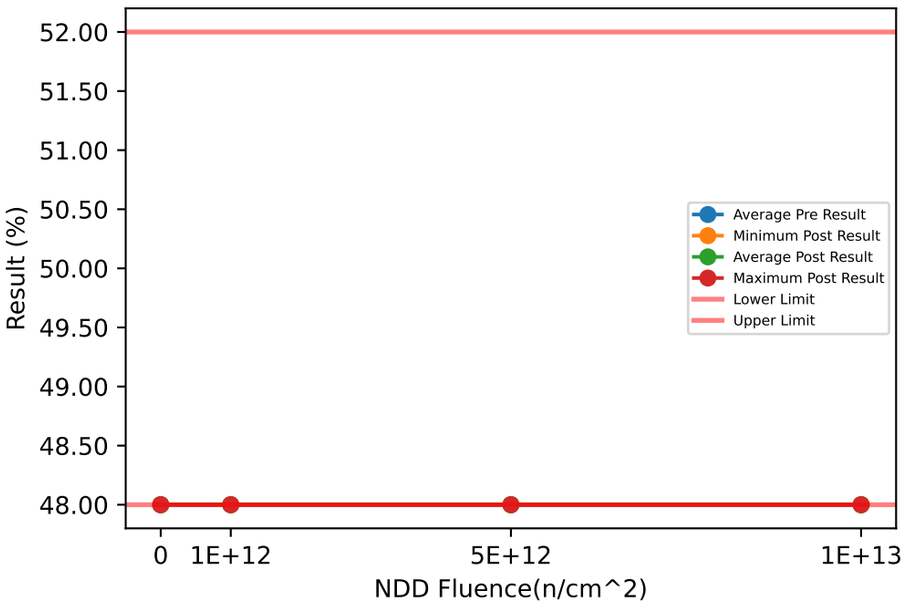
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	494.24	494.53	0.2888
466	1e+12	NDD	492.55	492.63	0.0804
762	0	CORRELATION	489.11	489.27	0.155
769	1e+12	NDD	492.05	492.04	-0.0164
887	1e+12	NDD	494.34	493.86	-0.4775
891	0	CORRELATION	499.2	499.33	0.1248
927	1e+12	NDD	489.4	489.44	0.0426
967	5e+12	NDD	496.12	495.88	-0.245
1204	1e+13	NDD	493.68	493.58	-0.1005
1284	1e+13	NDD	492.16	492.69	0.5311
1292	5e+12	NDD	492.45	492.29	-0.1648
1364	1e+13	NDD	487.18	487.8	0.6175
1383	5e+12	NDD	494.58	494.82	0.2436
1388	5e+12	NDD	490.65	490.68	0.0325
1427	1e+13	NDD	490.45	490.33	-0.1206
1666	0	CORRELATION	495.56	495.36	-0.2037

Test Statistics (kHz)

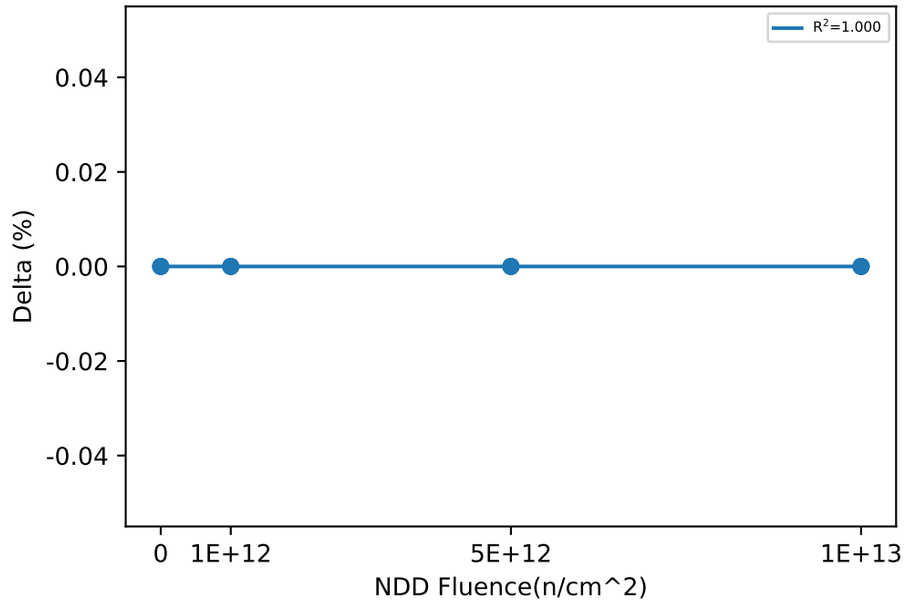
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	489.11	494.53	499.2	4.1773	489.27	494.62	499.33	4.1385	-0.2037	0.091225	0.2888	0.20913
1e+12	489.4	492.08	494.34	2.0405	489.44	491.99	493.86	1.8609	-0.4775	-0.092725	0.0804	0.25959
5e+12	490.65	493.45	496.12	2.3982	490.68	493.42	495.88	2.3652	-0.245	-0.033425	0.2436	0.21841
1e+13	487.18	490.87	493.68	2.7891	487.8	491.1	493.58	2.5925	-0.1206	0.23187	0.6175	0.39705

Device Test: 20.49 PF|DCL_48/SYNC/12/12/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

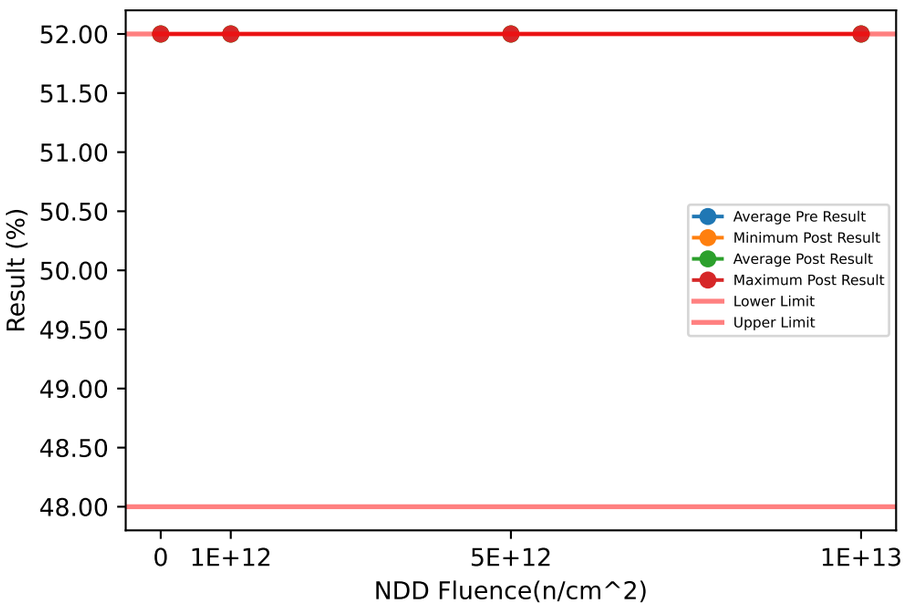
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

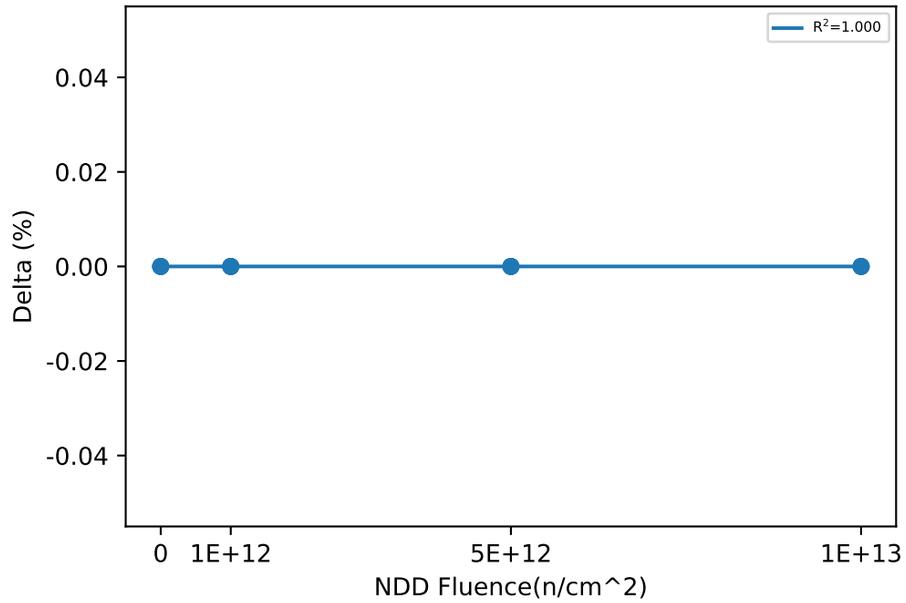
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.50 PF|DCL_52/SYNC/12/12/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

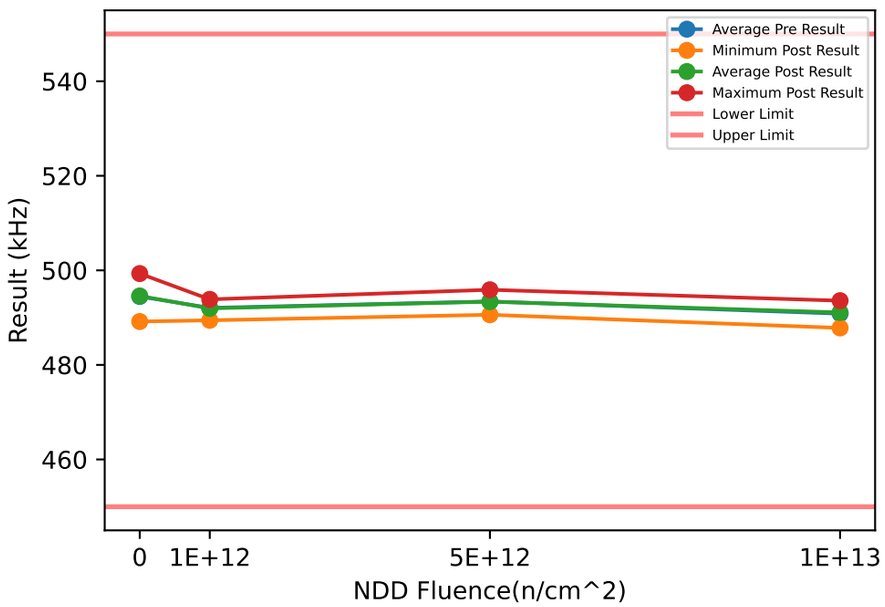
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

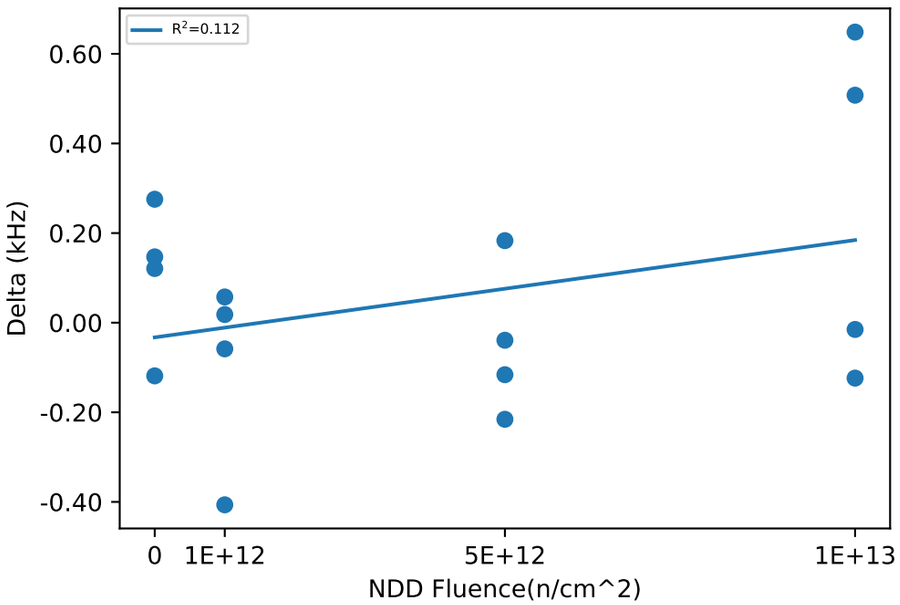
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.51 LEVEL|FREQ/RT/14/14/0/0/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

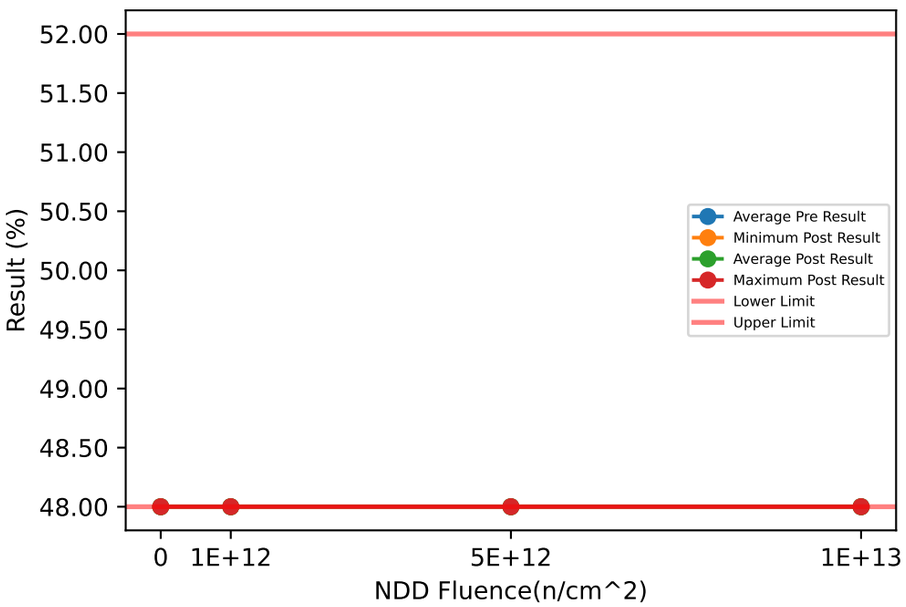
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	494.19	494.47	0.2755
466	1e+12	NDD	492.57	492.59	0.0182
762	0	CORRELATION	489.05	489.17	0.1209
769	1e+12	NDD	492.02	491.96	-0.0584
887	1e+12	NDD	494.27	493.86	-0.4065
891	0	CORRELATION	499.17	499.32	0.1469
927	1e+12	NDD	489.37	489.43	0.0574
967	5e+12	NDD	496.11	495.89	-0.2156
1204	1e+13	NDD	493.6	493.58	-0.0151
1284	1e+13	NDD	492.15	492.66	0.5077
1292	5e+12	NDD	492.37	492.26	-0.1161
1364	1e+13	NDD	487.17	487.82	0.6486
1383	5e+12	NDD	494.55	494.74	0.1831
1388	5e+12	NDD	490.65	490.61	-0.0392
1427	1e+13	NDD	490.45	490.33	-0.1237
1666	0	CORRELATION	495.48	495.36	-0.1187

Test Statistics (kHz)

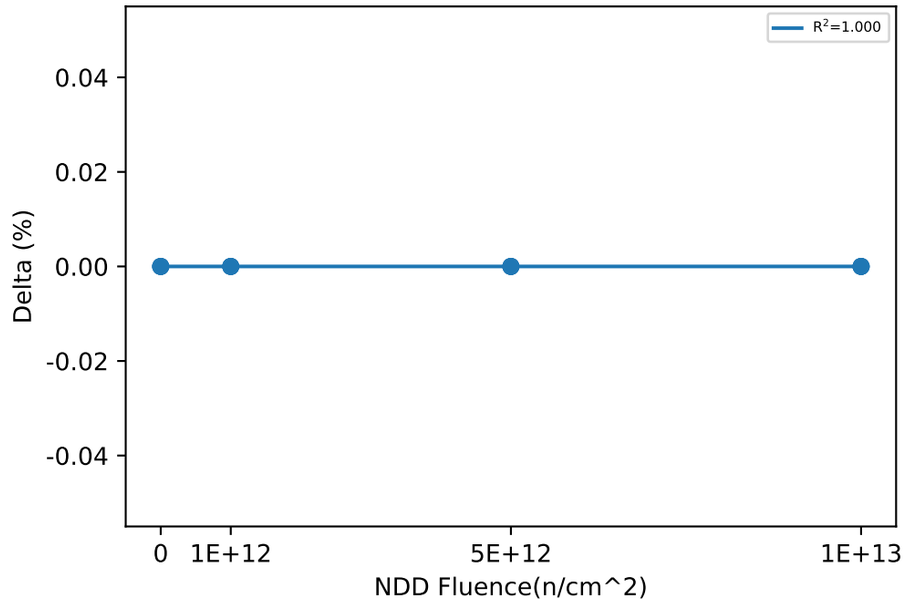
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	489.05	494.47	499.17	4.187	489.17	494.58	499.32	4.1773	-0.1187	0.10615	0.2755	0.16443
1e+12	489.37	492.06	494.27	2.0298	489.43	491.96	493.86	1.863	-0.4065	-0.097325	0.0574	0.21165
5e+12	490.65	493.42	496.11	2.4008	490.61	493.37	495.89	2.3871	-0.2156	-0.04695	0.1831	0.16952
1e+13	487.17	490.84	493.6	2.7652	487.82	491.1	493.58	2.5788	-0.1237	0.25438	0.6486	0.38085

Device Test: 20.53 PF|DCL_48/SYNC/14/14/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

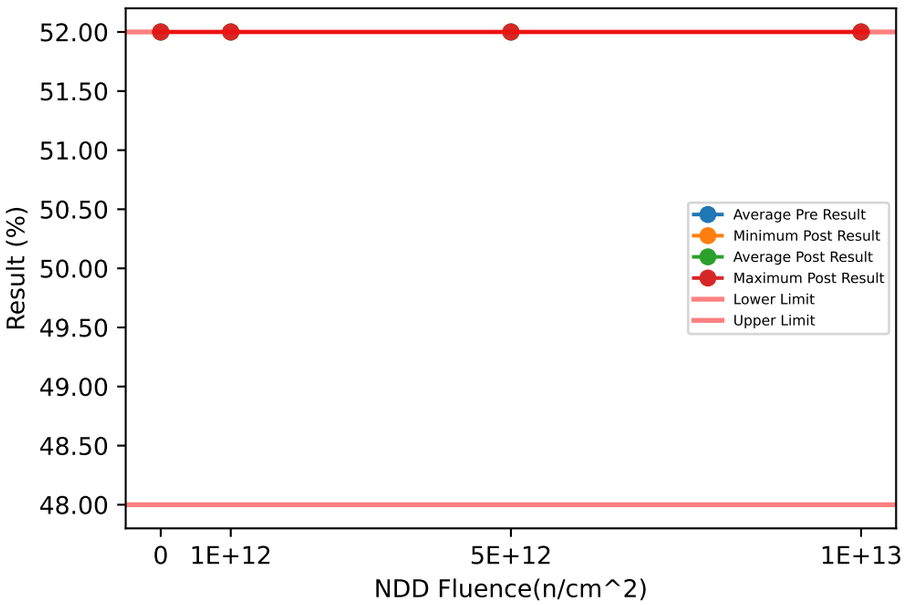
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

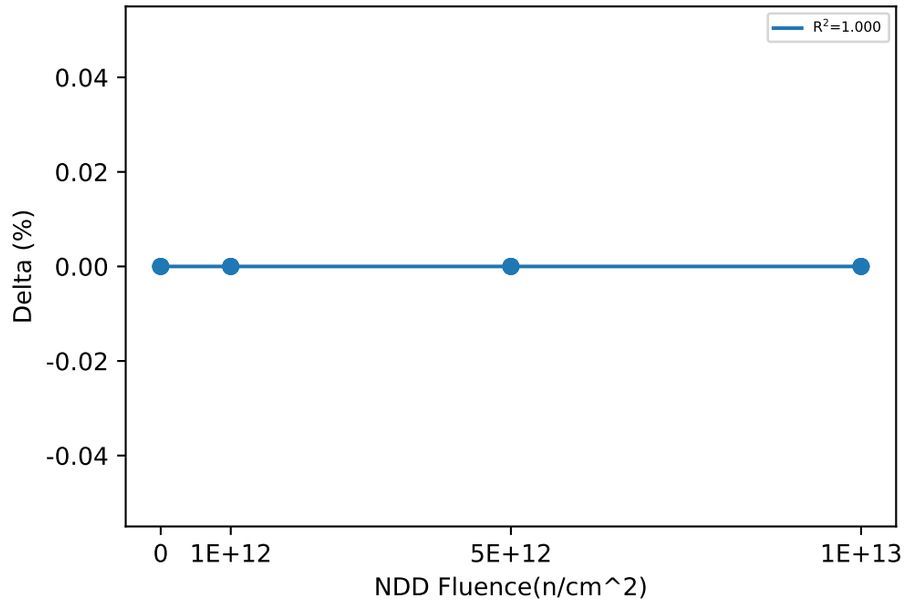
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.54 PF|DCL_52/SYNC/14/14/0/0/5/500kHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

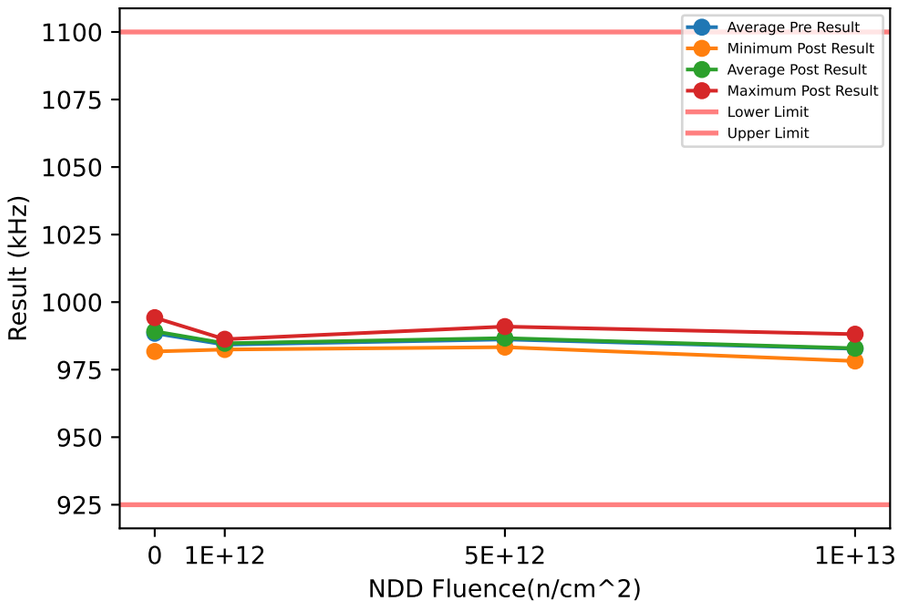
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

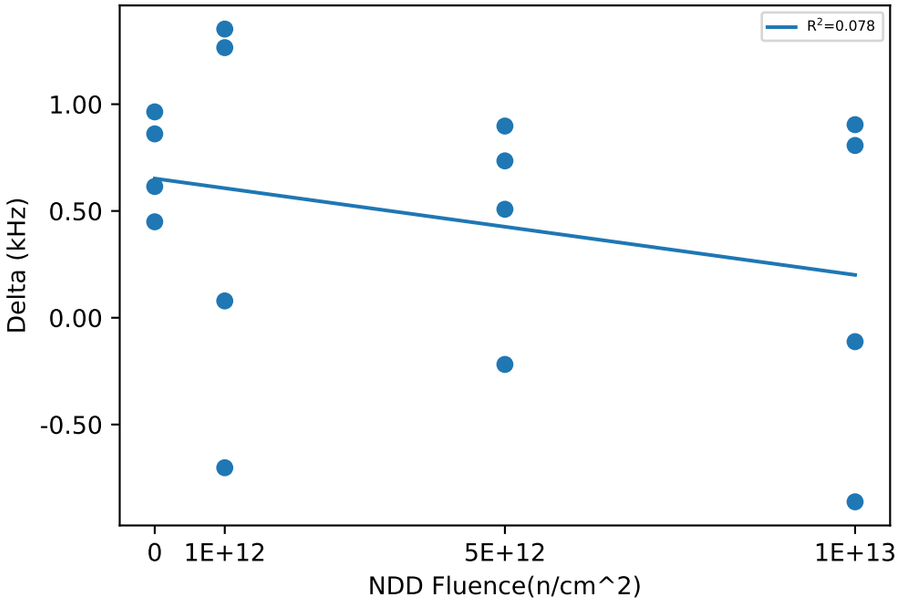
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.55 LEVEL|FREQ/RT/4.5/4.5/0/0/4.5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



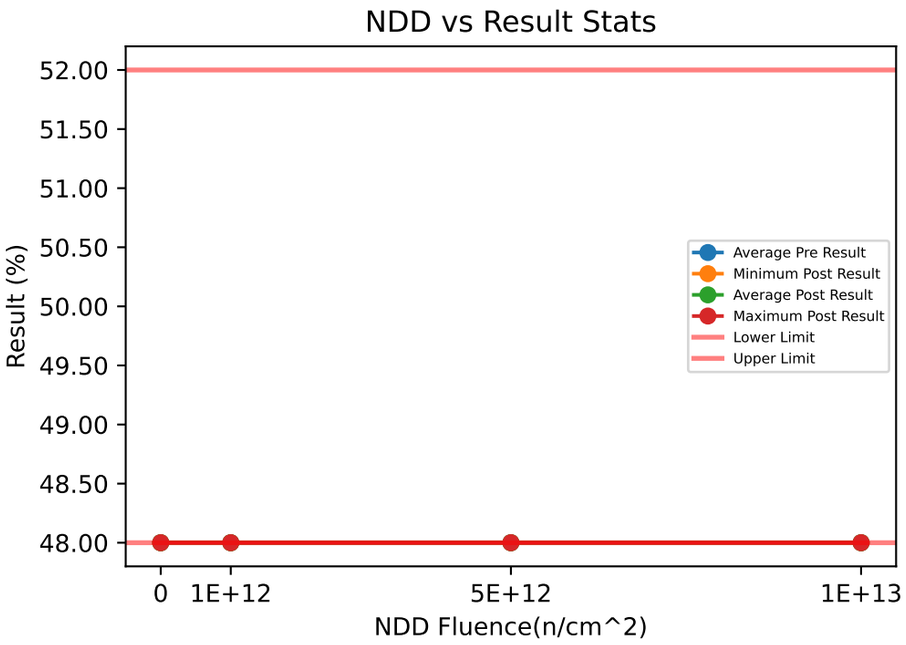
Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

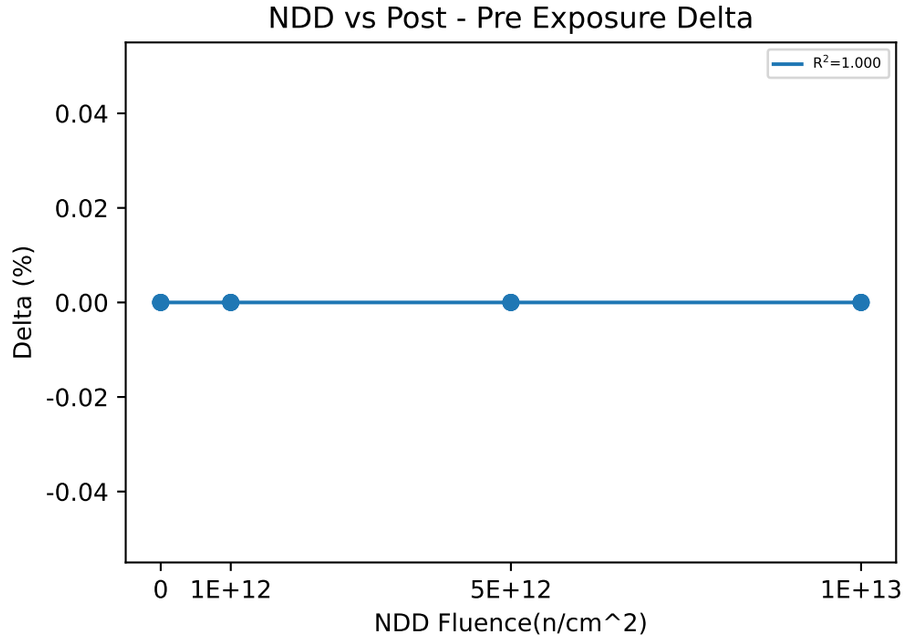
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	989.3	989.75	0.4493
466	1e+12	NDD	984.27	984.35	0.0788
762	0	CORRELATION	981.11	981.73	0.6146
769	1e+12	NDD	985	986.26	1.2649
887	1e+12	NDD	986.67	985.96	-0.7024
891	0	CORRELATION	993.29	994.25	0.9641
927	1e+12	NDD	981.1	982.45	1.3518
967	5e+12	NDD	990.04	990.94	0.8977
1204	1e+13	NDD	988.25	988.13	-0.112
1284	1e+13	NDD	983.01	982.15	-0.862
1292	5e+12	NDD	983.94	984.45	0.508
1364	1e+13	NDD	977.38	978.19	0.8067
1383	5e+12	NDD	987.23	987.96	0.7346
1388	5e+12	NDD	983.54	983.33	-0.2186
1427	1e+13	NDD	982.29	983.2	0.9041
1666	0	CORRELATION	990.13	990.99	0.861

Test Statistics (kHz)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	981.11	988.46	993.29	5.1905	981.73	989.18	994.25	5.3201	0.4493	0.72225	0.9641	0.23369
1e+12	981.1	984.26	986.67	2.3332	982.45	984.75	986.26	1.7521	-0.7024	0.49828	1.3518	0.9889
5e+12	983.54	986.19	990.04	3.0531	983.33	986.67	990.94	3.4646	-0.2186	0.48042	0.8977	0.49265
1e+13	977.38	982.73	988.25	4.4458	978.19	982.92	988.13	4.0925	-0.862	0.1842	0.9041	0.83427

Device Test: 20.57 PF|DCL_48/SYNC/4.5/4.5/0/0/4.5/1MHz//@DUTY_SYNC_EXT_DCL50





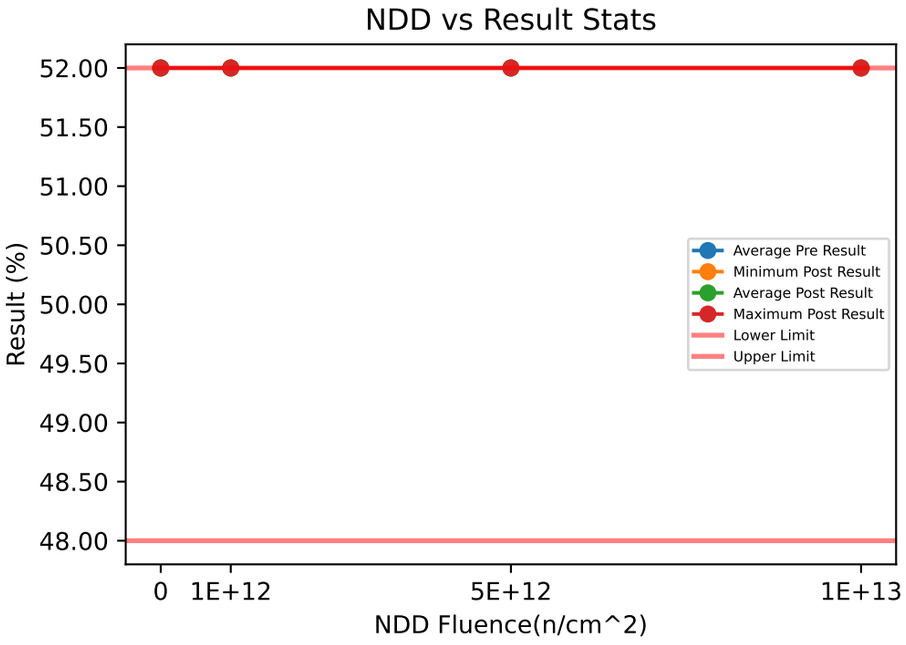
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

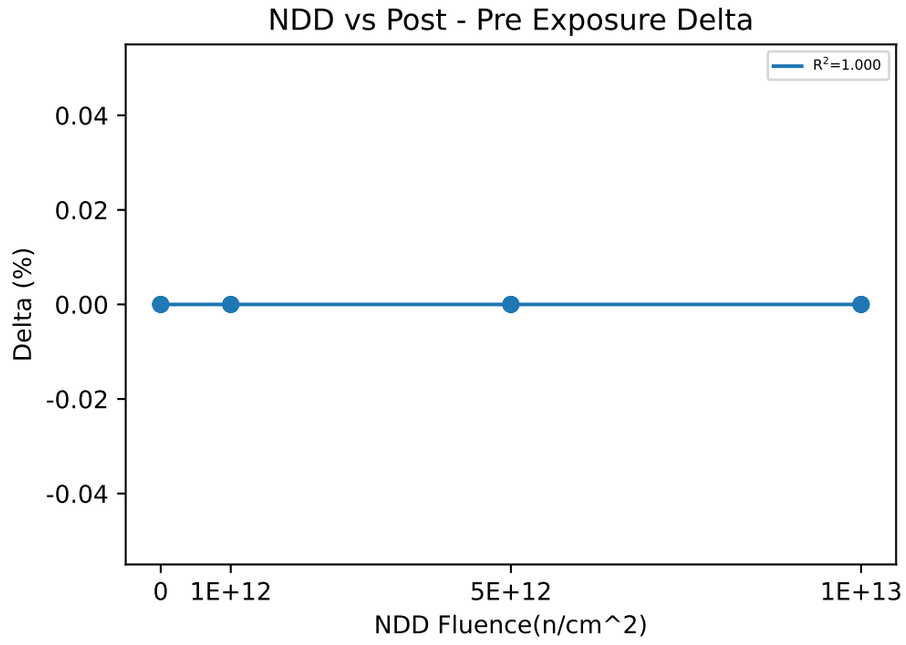
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.58 PF|DCL_52/SYNC/4.5/4.5/0/0/4.5/1MHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

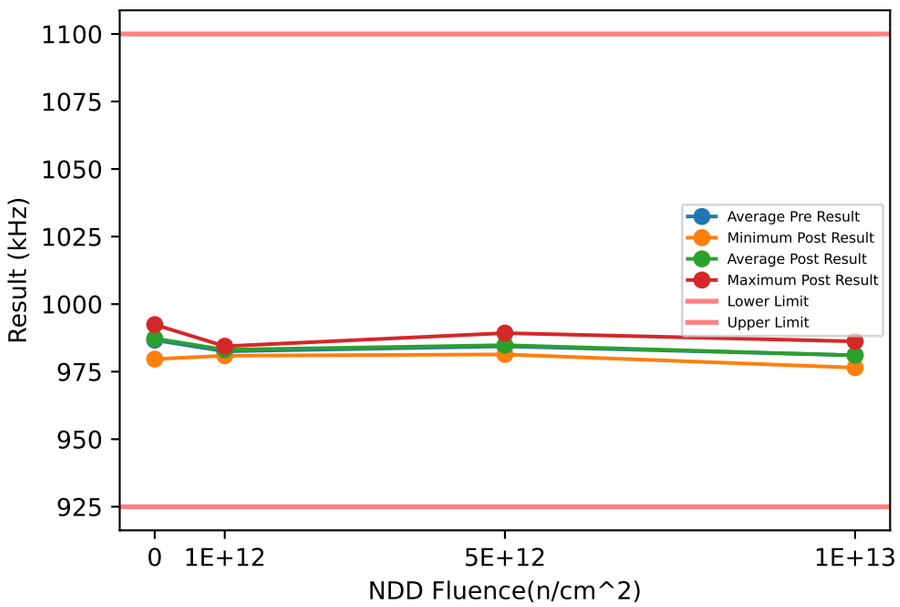
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

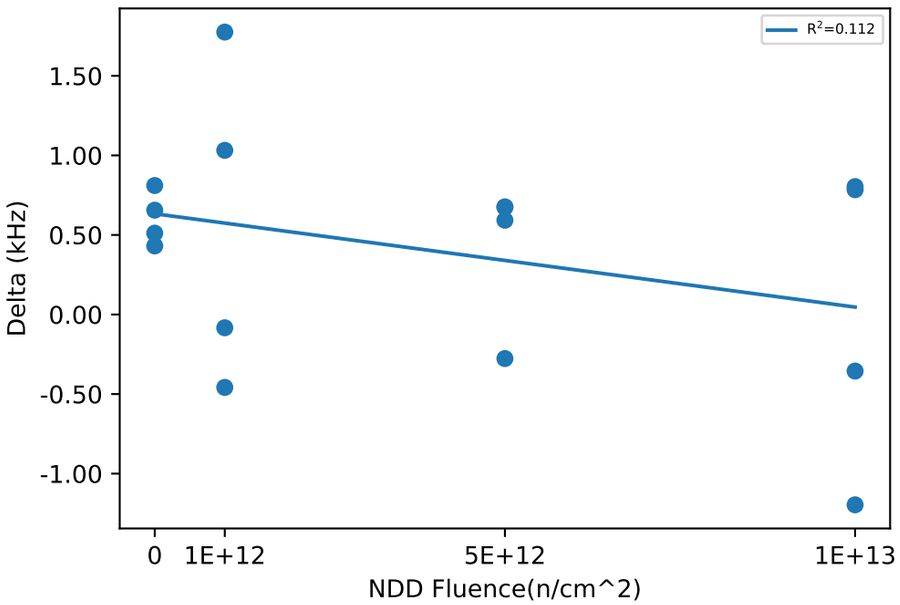
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.59 LEVEL|FREQ/RT/5/5/0/0/5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

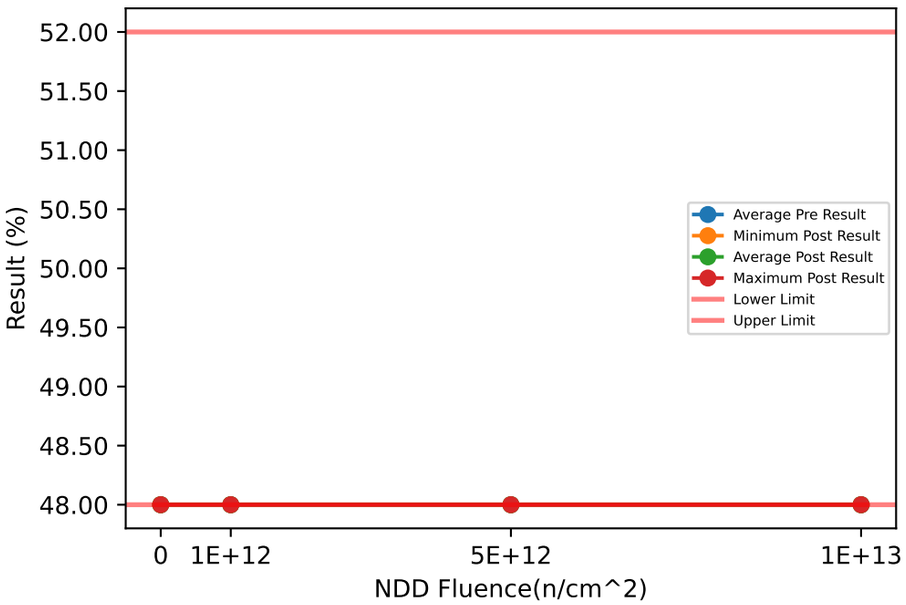
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	987.34	987.85	0.5114
466	1e+12	NDD	982.82	982.74	-0.0834
762	0	CORRELATION	979.22	979.65	0.4311
769	1e+12	NDD	983.37	984.4	1.0318
887	1e+12	NDD	984.84	984.39	-0.4581
891	0	CORRELATION	991.62	992.43	0.8107
927	1e+12	NDD	979.12	980.9	1.775
967	5e+12	NDD	988.6	989.27	0.6744
1204	1e+13	NDD	986.57	986.21	-0.3554
1284	1e+13	NDD	981.43	980.24	-1.196
1292	5e+12	NDD	982.03	982.62	0.5926
1364	1e+13	NDD	975.69	976.48	0.7842
1383	5e+12	NDD	985.25	985.93	0.6764
1388	5e+12	NDD	981.65	981.37	-0.2768
1427	1e+13	NDD	980.46	981.26	0.8039
1666	0	CORRELATION	988.5	989.15	0.6557

Test Statistics (kHz)

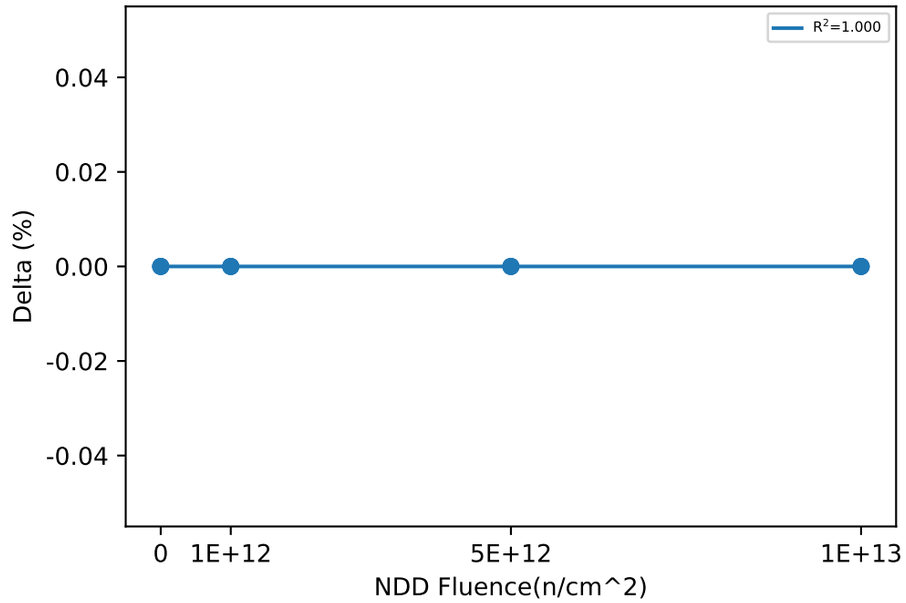
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	979.22	986.67	991.62	5.2835	979.65	987.27	992.43	5.4319	0.4311	0.60222	0.8107	0.16719
1e+12	979.12	982.54	984.84	2.4322	980.9	983.11	984.4	1.6659	-0.4581	0.56633	1.775	1.0246
5e+12	981.65	984.38	988.6	3.2428	981.37	984.8	989.27	3.5489	-0.2768	0.41665	0.6764	0.46395
1e+13	975.69	981.04	986.57	4.4597	976.48	981.05	986.21	4.0119	-1.196	0.009175	0.8039	0.96913

Device Test: 20.61 PF|DCL_48/SYNC/5/5/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

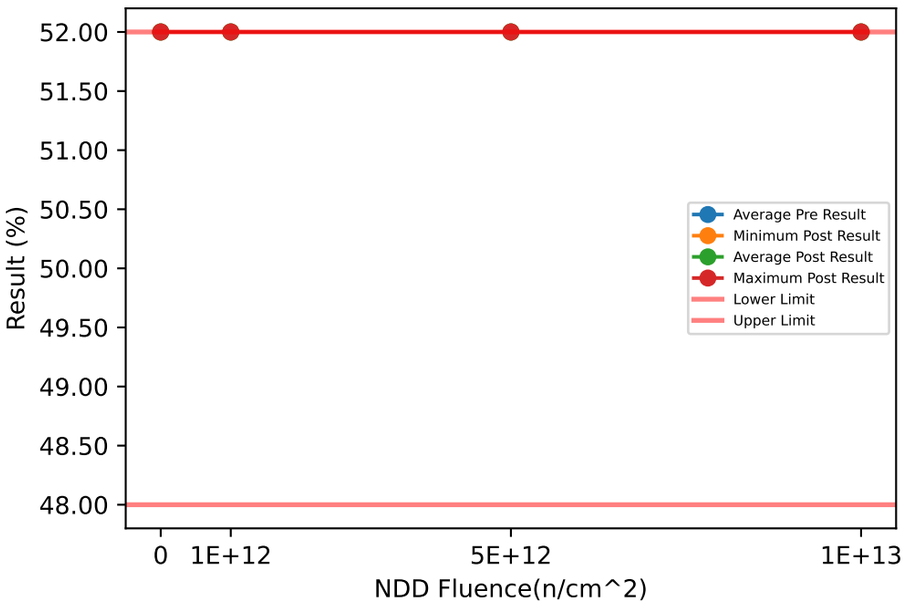
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

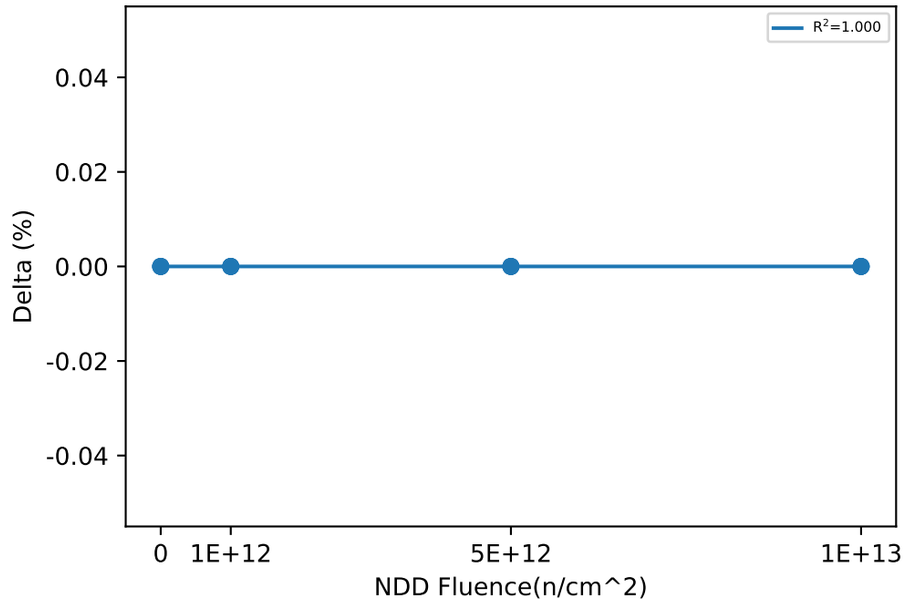
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.62 PF|DCL_52/SYNC/5/5/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

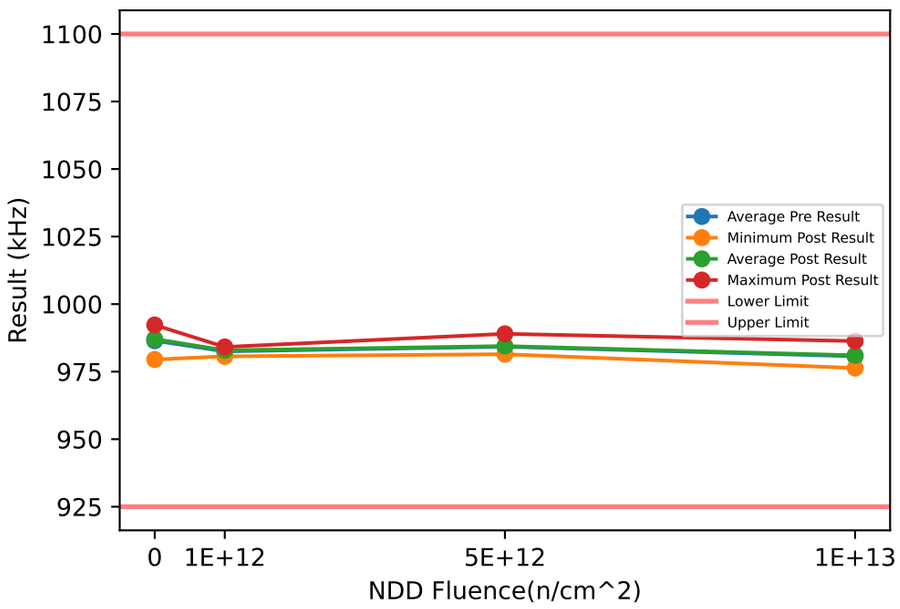
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

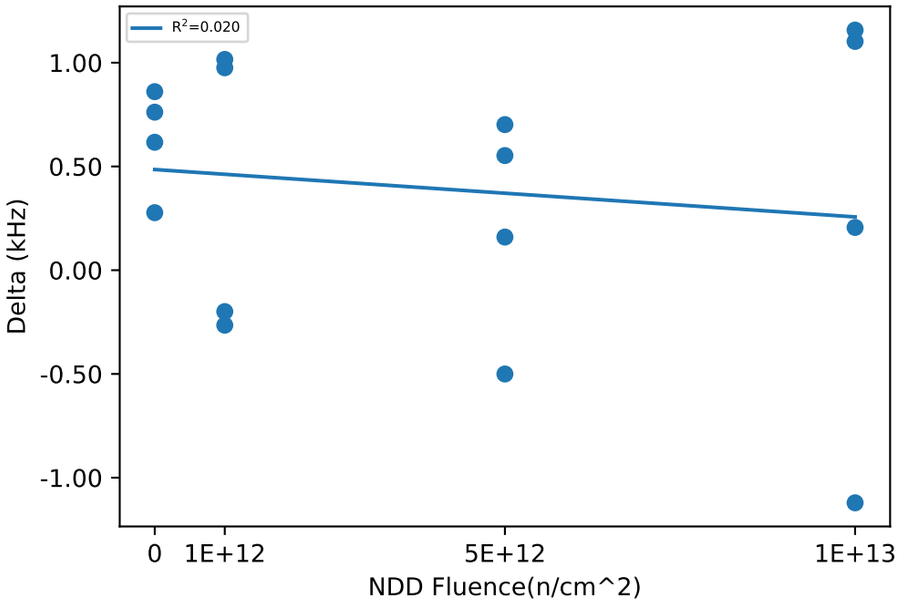
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.63 LEVEL|FREQ/RT/12/12/0/0/5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

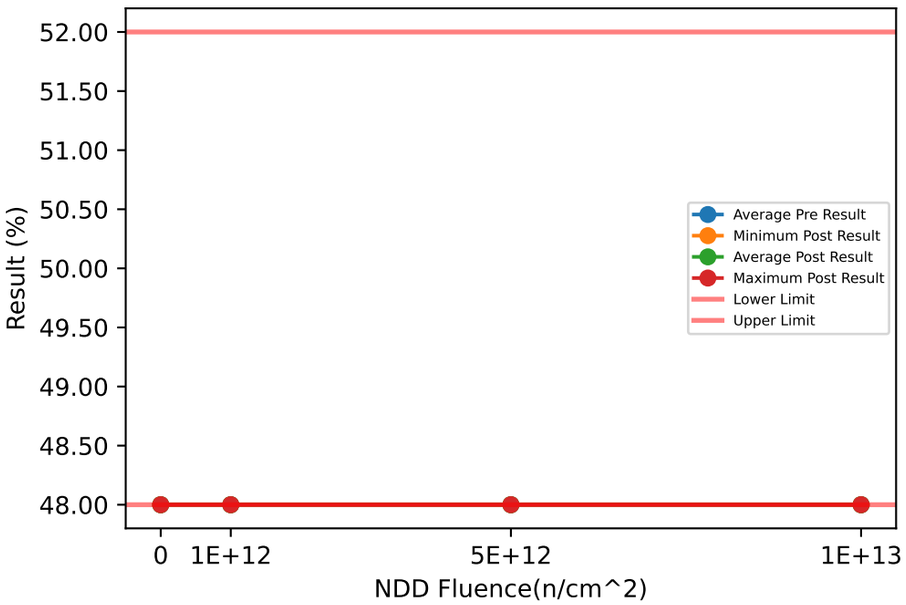
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	987.33	987.61	0.2772
466	1e+12	NDD	982.86	982.66	-0.1995
762	0	CORRELATION	978.88	979.5	0.6165
769	1e+12	NDD	983.13	984.11	0.9755
887	1e+12	NDD	984.4	984.13	-0.2651
891	0	CORRELATION	991.42	992.28	0.8604
927	1e+12	NDD	979.65	980.66	1.0158
967	5e+12	NDD	988.3	989.01	0.7016
1204	1e+13	NDD	986.11	986.32	0.206
1284	1e+13	NDD	981.19	980.07	-1.1211
1292	5e+12	NDD	981.9	982.45	0.5524
1364	1e+13	NDD	975.23	976.33	1.1026
1383	5e+12	NDD	984.79	984.95	0.1597
1388	5e+12	NDD	981.95	981.45	-0.5003
1427	1e+13	NDD	980.26	981.42	1.1572
1666	0	CORRELATION	988.2	988.96	0.7616

Test Statistics (kHz)

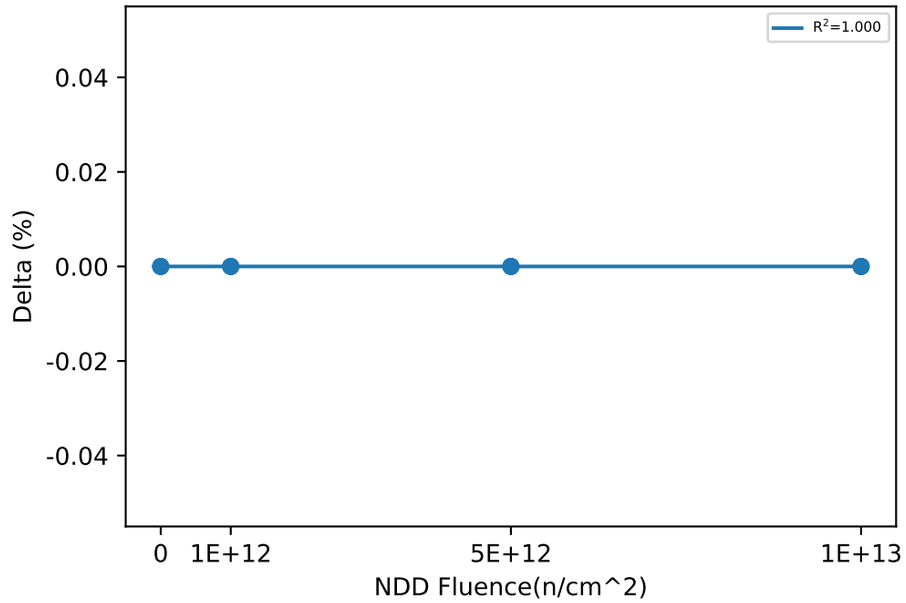
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	978.88	986.46	991.42	5.3493	979.5	987.09	992.28	5.4275	0.2772	0.62892	0.8604	0.25498
1e+12	979.65	982.51	984.4	2.0226	980.66	982.89	984.13	1.6376	-0.2651	0.38167	1.0158	0.70965
5e+12	981.9	984.24	988.3	3.0282	981.45	984.47	989.01	3.3646	-0.5003	0.22835	0.7016	0.53685
1e+13	975.23	980.7	986.11	4.4603	976.33	981.03	986.32	4.129	-1.1211	0.33617	1.1572	1.0649

Device Test: 20.65 PF|DCL_48/SYNC/12/12/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



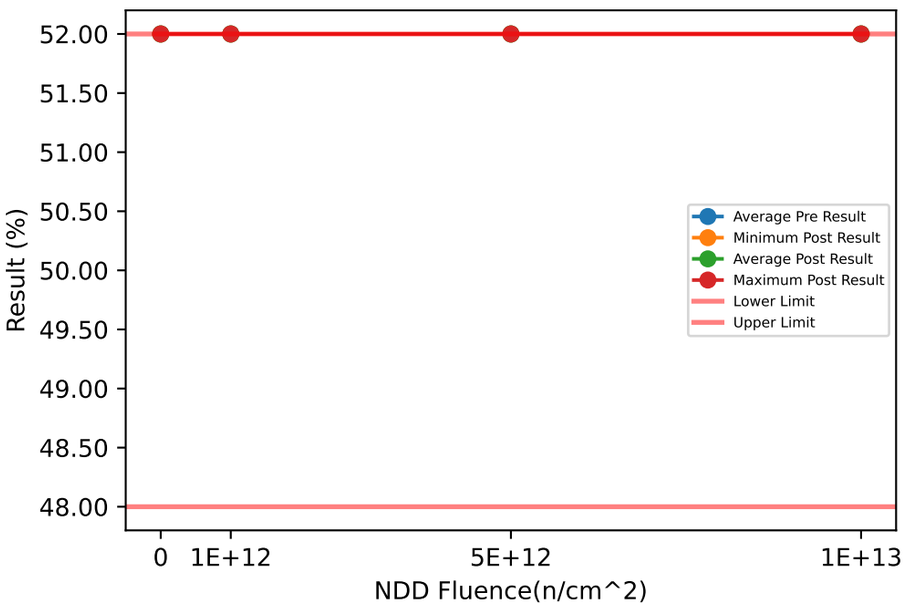
Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

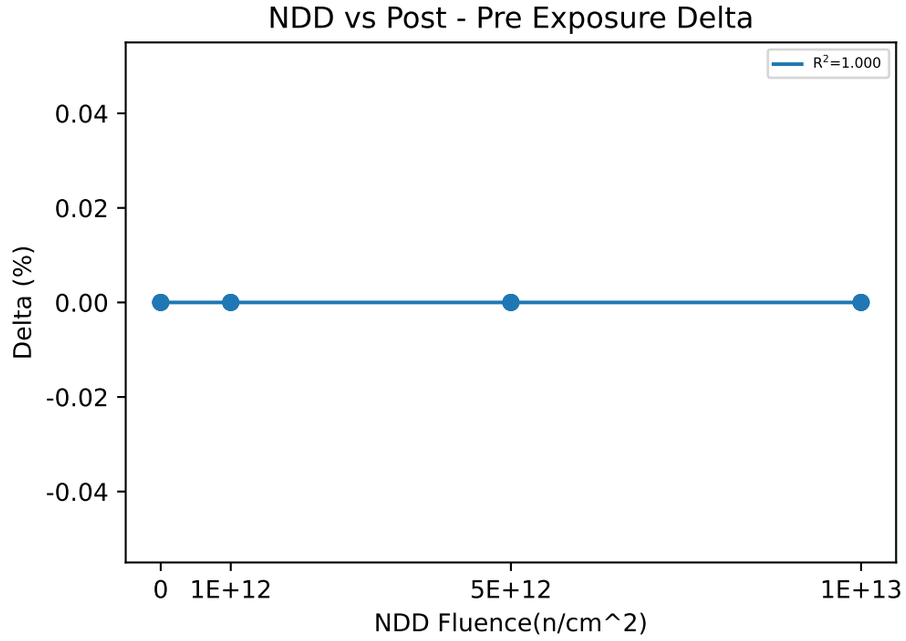
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.66 PF|DCL_52/SYNC/12/12/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50





Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

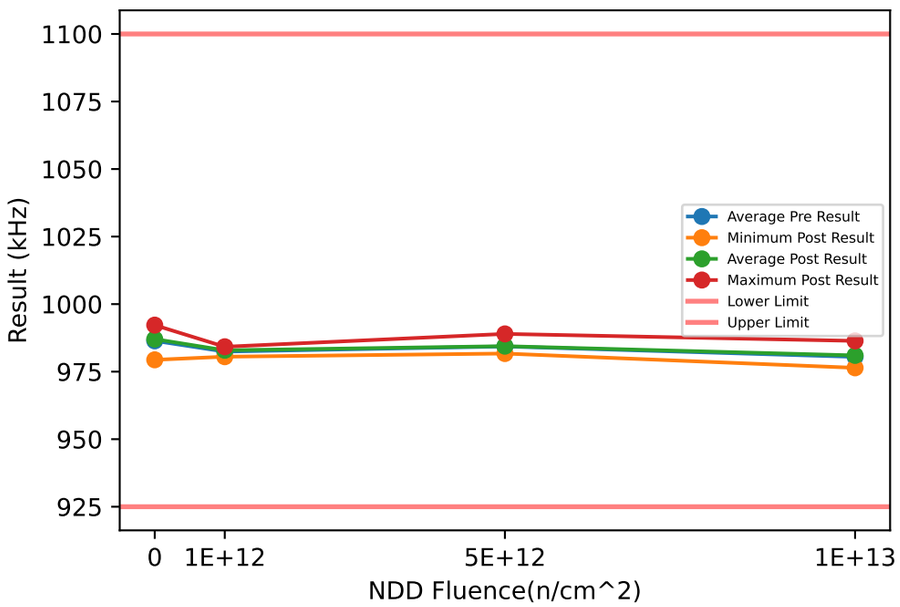
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

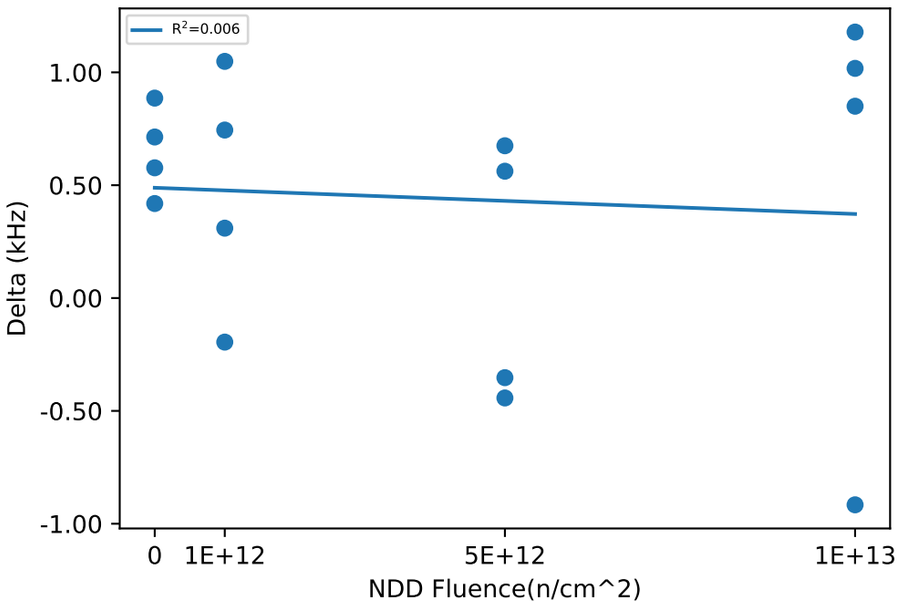
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.67 LEVEL|FREQ/RT/14/14/0/0/5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

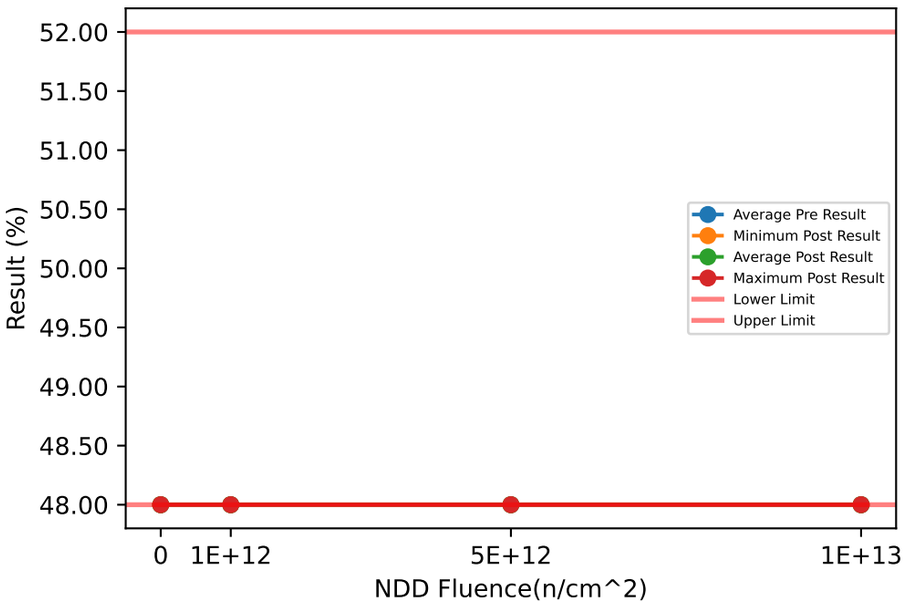
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	987.21	987.63	0.4188
466	1e+12	NDD	982.48	982.79	0.3097
762	0	CORRELATION	978.8	979.38	0.5771
769	1e+12	NDD	983.03	984.08	1.0487
887	1e+12	NDD	984.41	984.21	-0.1952
891	0	CORRELATION	991.51	992.23	0.7136
927	1e+12	NDD	979.79	980.53	0.7444
967	5e+12	NDD	988.41	988.97	0.562
1204	1e+13	NDD	985.54	986.39	0.85
1284	1e+13	NDD	980.81	979.89	-0.9162
1292	5e+12	NDD	981.8	982.48	0.6748
1364	1e+13	NDD	975.24	976.42	1.1785
1383	5e+12	NDD	984.95	984.6	-0.3528
1388	5e+12	NDD	982.15	981.7	-0.4427
1427	1e+13	NDD	980.33	981.35	1.0177
1666	0	CORRELATION	988.08	988.96	0.8859

Test Statistics (kHz)

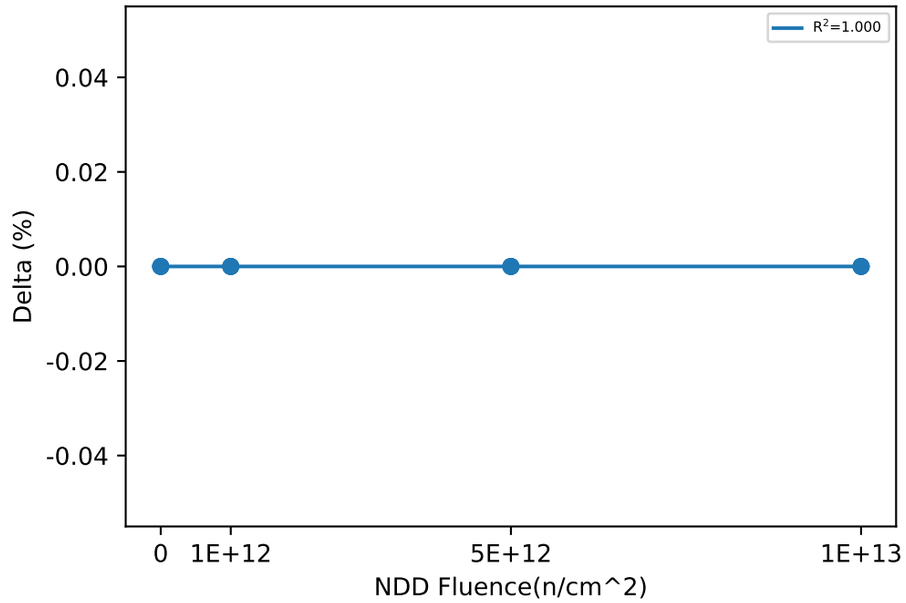
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	978.8	986.4	991.51	5.3958	979.38	987.05	992.23	5.4662	0.4188	0.64885	0.8859	0.19871
1e+12	979.79	982.43	984.41	1.937	980.53	982.9	984.21	1.7061	-0.1952	0.4769	1.0487	0.54104
5e+12	981.8	984.33	988.41	3.0665	981.7	984.44	988.97	3.2622	-0.4427	0.11032	0.6748	0.58962
1e+13	975.24	980.48	985.54	4.2126	976.42	981.01	986.39	4.1407	-0.9162	0.5325	1.1785	0.97507

Device Test: 20.69 PF|DCL_48/SYNC/14/14/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

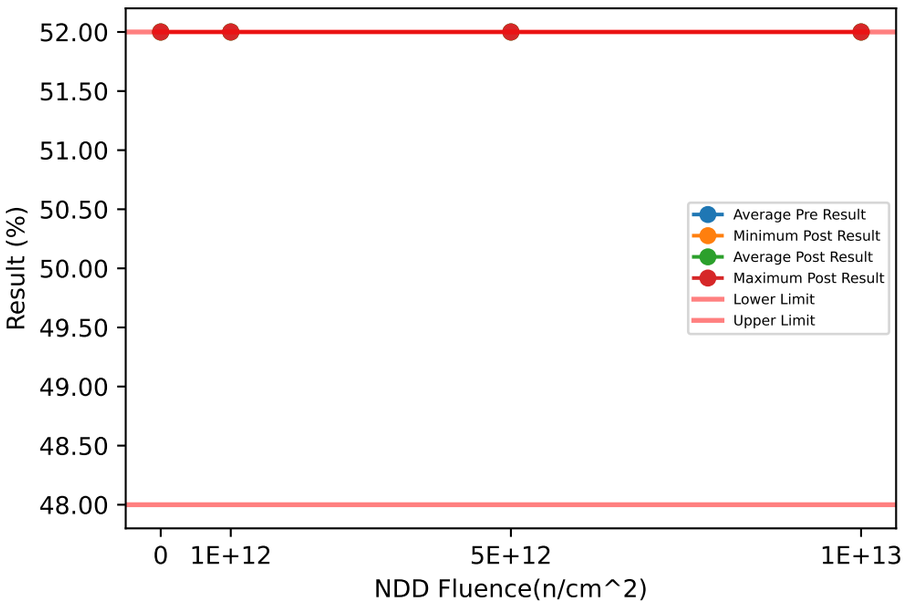
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	48	48	0
466	1e+12	NDD	48	48	0
762	0	CORRELATION	48	48	0
769	1e+12	NDD	48	48	0
887	1e+12	NDD	48	48	0
891	0	CORRELATION	48	48	0
927	1e+12	NDD	48	48	0
967	5e+12	NDD	48	48	0
1204	1e+13	NDD	48	48	0
1284	1e+13	NDD	48	48	0
1292	5e+12	NDD	48	48	0
1364	1e+13	NDD	48	48	0
1383	5e+12	NDD	48	48	0
1388	5e+12	NDD	48	48	0
1427	1e+13	NDD	48	48	0
1666	0	CORRELATION	48	48	0

Test Statistics (%)

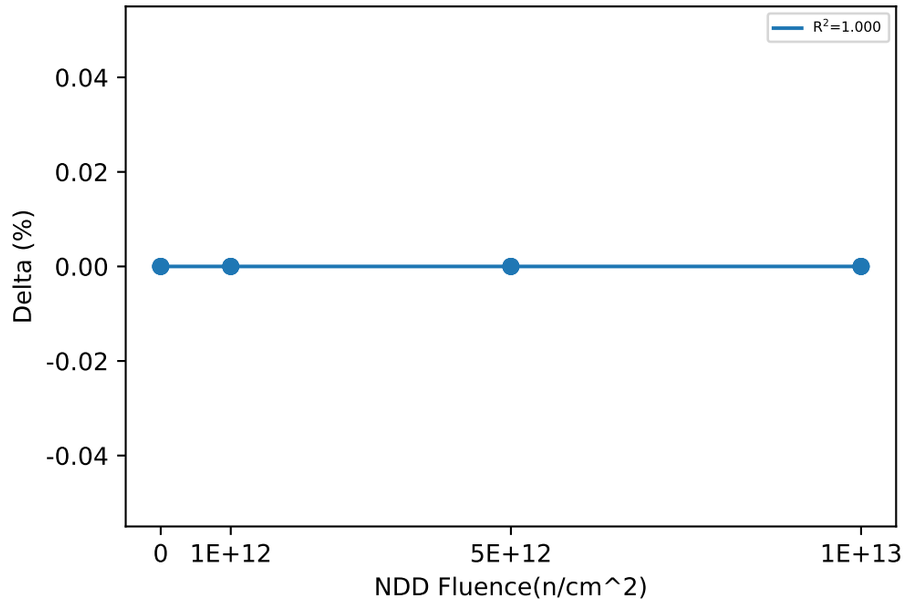
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	48	48	48	0	48	48	48	0	0	0	0	0
1e+12	48	48	48	0	48	48	48	0	0	0	0	0
5e+12	48	48	48	0	48	48	48	0	0	0	0	0
1e+13	48	48	48	0	48	48	48	0	0	0	0	0

Device Test: 20.70 PF|DCL_52/SYNC/14/14/0/0/5/1MHz//@DUTY_SYNC_EXT_DCL50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 48.0, Upper Limit = 52.0 (%))

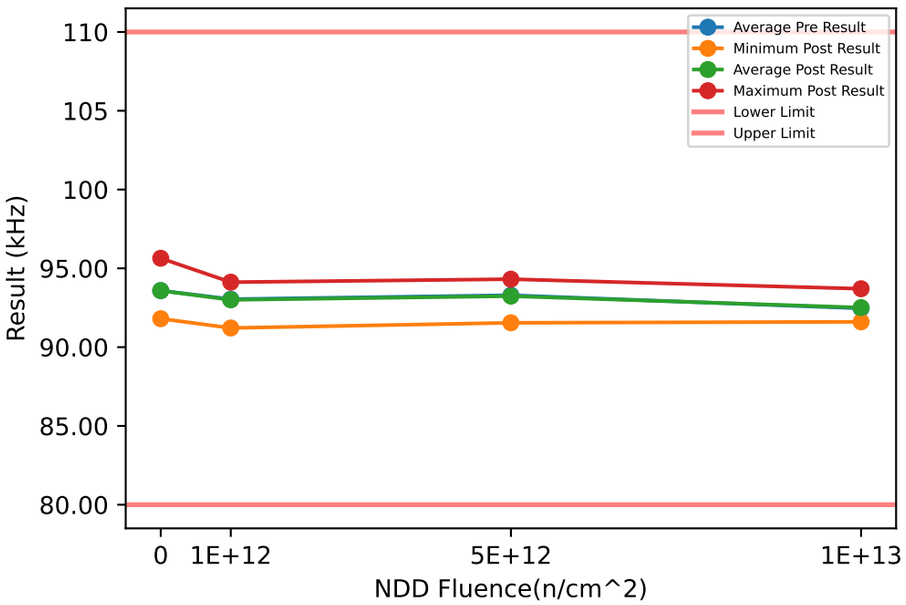
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52	52	0
466	1e+12	NDD	52	52	0
762	0	CORRELATION	52	52	0
769	1e+12	NDD	52	52	0
887	1e+12	NDD	52	52	0
891	0	CORRELATION	52	52	0
927	1e+12	NDD	52	52	0
967	5e+12	NDD	52	52	0
1204	1e+13	NDD	52	52	0
1284	1e+13	NDD	52	52	0
1292	5e+12	NDD	52	52	0
1364	1e+13	NDD	52	52	0
1383	5e+12	NDD	52	52	0
1388	5e+12	NDD	52	52	0
1427	1e+13	NDD	52	52	0
1666	0	CORRELATION	52	52	0

Test Statistics (%)

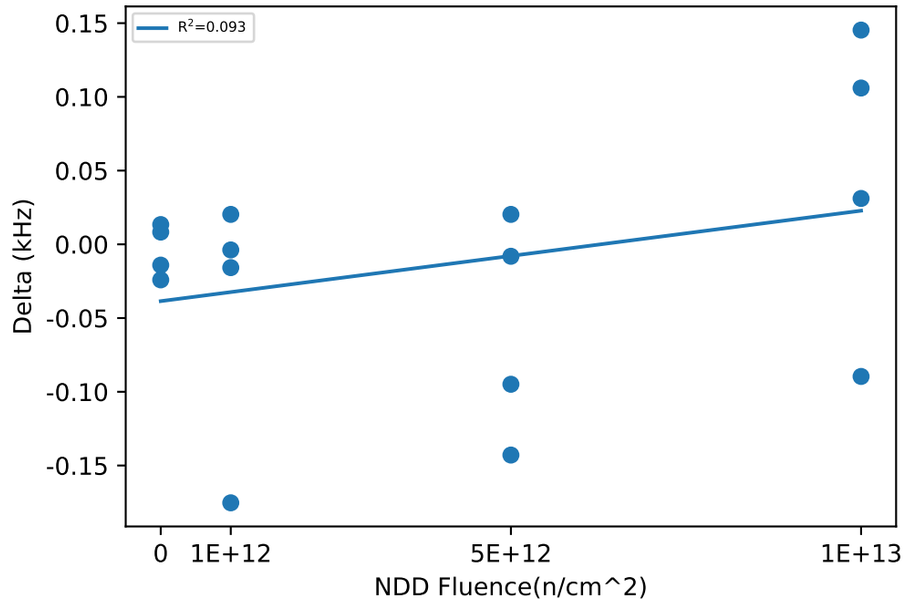
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52	52	52	0	52	52	52	0	0	0	0	0
1e+12	52	52	52	0	52	52	52	0	0	0	0	0
5e+12	52	52	52	0	52	52	52	0	0	0	0	0
1e+13	52	52	52	0	52	52	52	0	0	0	0	0

Device Test: 20.71 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

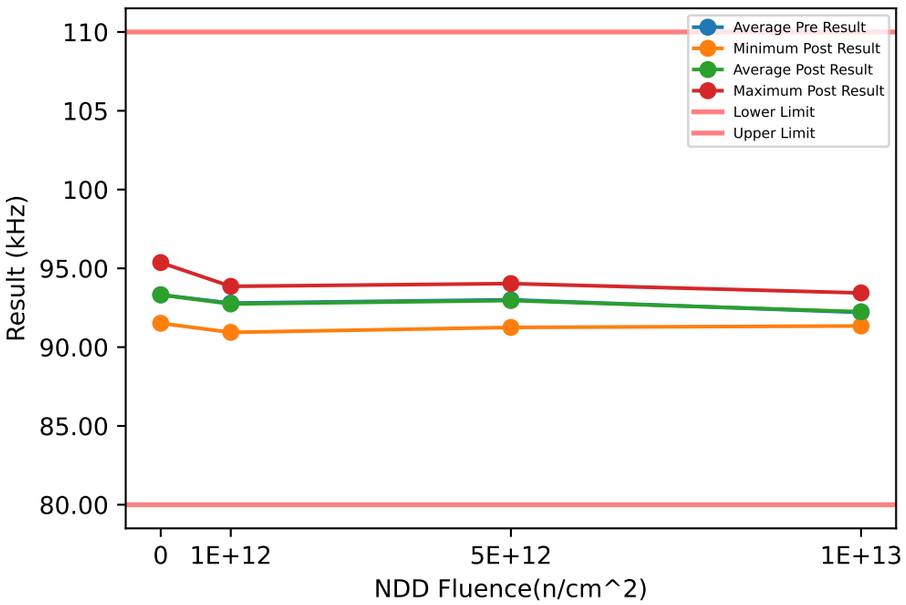
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	93.032	93.008	-0.0241
466	1e+12	NDD	93.825	93.809	-0.0158
762	0	CORRELATION	91.791	91.805	0.0134
769	1e+12	NDD	92.86	92.856	-0.0038
887	1e+12	NDD	94.298	94.122	-0.1753
891	0	CORRELATION	95.632	95.641	0.0083
927	1e+12	NDD	91.195	91.216	0.0203
967	5e+12	NDD	94.292	94.313	0.0203
1204	1e+13	NDD	92.769	92.68	-0.0896
1284	1e+13	NDD	93.56	93.706	0.1453
1292	5e+12	NDD	93.143	93	-0.1429
1364	1e+13	NDD	91.5	91.606	0.106
1383	5e+12	NDD	94.097	94.089	-0.0081
1388	5e+12	NDD	91.64	91.545	-0.0949
1427	1e+13	NDD	92.016	92.047	0.0311
1666	0	CORRELATION	93.896	93.882	-0.0141

Test Statistics (kHz)

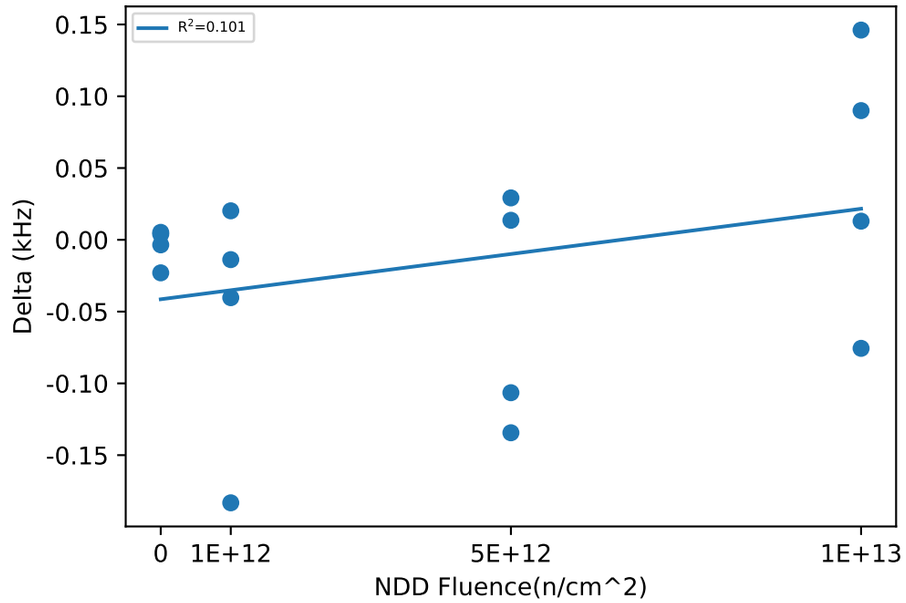
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.791	93.588	95.632	1.6137	91.805	93.584	95.641	1.6142	-0.0241	-0.004125	0.0134	0.017889
1e+12	91.195	93.044	94.298	1.3701	91.216	93.001	94.122	1.3061	-0.1753	-0.04365	0.0203	0.089041
5e+12	91.64	93.293	94.292	1.2112	91.545	93.237	94.313	1.2652	-0.1429	-0.0564	0.0203	0.075675
1e+13	91.5	92.461	93.56	0.89914	91.606	92.51	93.706	0.91105	-0.0896	0.0482	0.1453	0.10336

Device Test: 20.73 LEVEL|FREQ/RT/5/5/0/1000/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

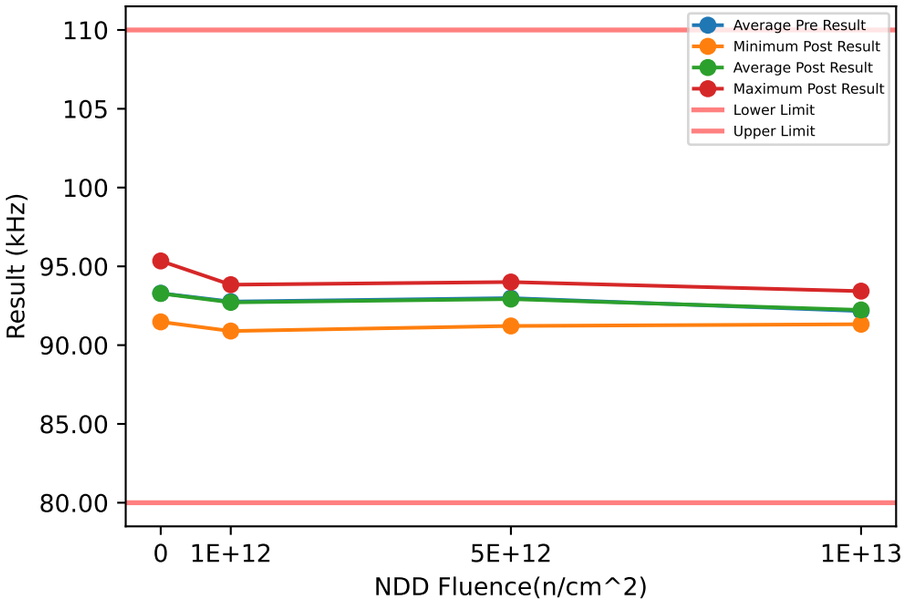
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	92.759	92.763	0.0039
466	1e+12	NDD	93.595	93.581	-0.0138
762	0	CORRELATION	91.512	91.517	0.0052
769	1e+12	NDD	92.624	92.583	-0.0403
887	1e+12	NDD	94.042	93.859	-0.1832
891	0	CORRELATION	95.371	95.367	-0.0035
927	1e+12	NDD	90.916	90.936	0.0202
967	5e+12	NDD	94.004	94.034	0.0292
1204	1e+13	NDD	92.507	92.431	-0.0756
1284	1e+13	NDD	93.295	93.441	0.1461
1292	5e+12	NDD	92.849	92.714	-0.1344
1364	1e+13	NDD	91.251	91.341	0.09
1383	5e+12	NDD	93.812	93.826	0.0136
1388	5e+12	NDD	91.359	91.252	-0.1065
1427	1e+13	NDD	91.757	91.77	0.013
1666	0	CORRELATION	93.642	93.619	-0.023

Test Statistics (kHz)

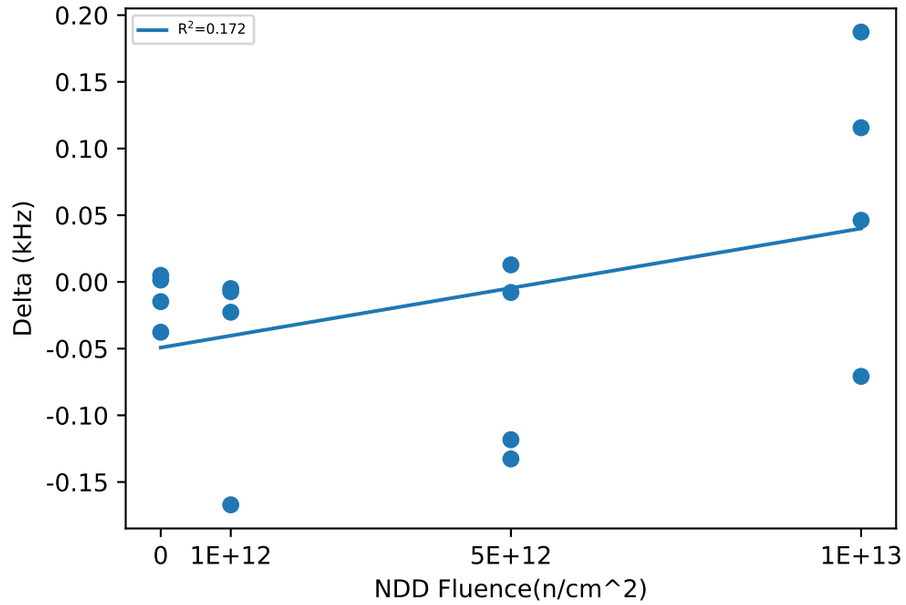
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.512	93.321	95.371	1.622	91.517	93.317	95.367	1.6167	-0.023	-0.00435	0.0052	0.01301
1e+12	90.916	92.794	94.042	1.3849	90.936	92.74	93.859	1.3212	-0.1832	-0.054275	0.0202	0.089446
5e+12	91.359	93.006	94.004	1.2091	91.252	92.956	94.034	1.2754	-0.1344	-0.049525	0.0292	0.08293
1e+13	91.251	92.203	93.295	0.89221	91.341	92.246	93.441	0.914	-0.0756	0.043375	0.1461	0.09627

Device Test: 20.75 LEVEL|FREQ/RT/12/12/0/1000/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

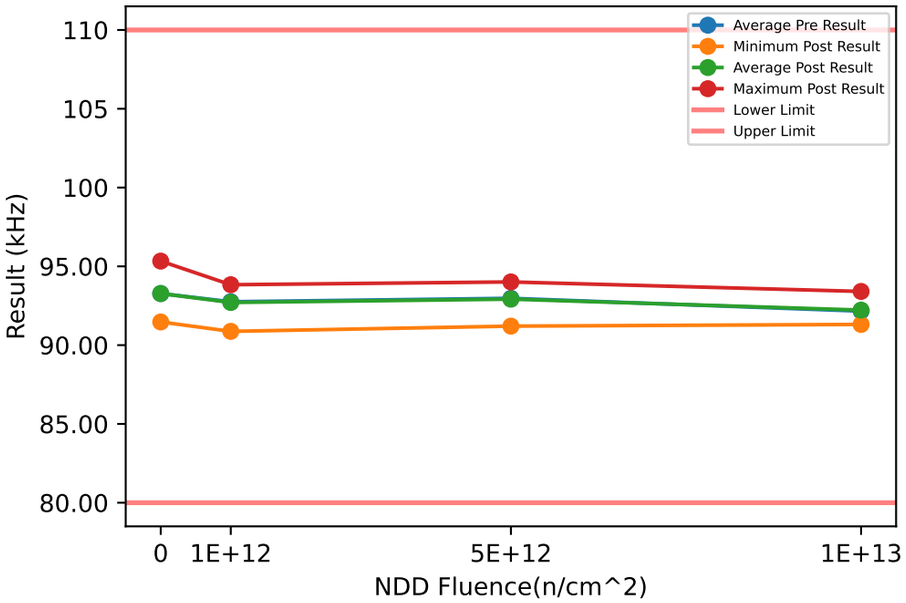
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	92.733	92.719	-0.0148
466	1e+12	NDD	93.564	93.556	-0.0073
762	0	CORRELATION	91.471	91.476	0.0049
769	1e+12	NDD	92.588	92.566	-0.0227
887	1e+12	NDD	94.003	93.836	-0.1671
891	0	CORRELATION	95.341	95.342	0.0014
927	1e+12	NDD	90.9	90.895	-0.005
967	5e+12	NDD	93.991	94.004	0.0128
1204	1e+13	NDD	92.486	92.415	-0.0708
1284	1e+13	NDD	93.24	93.427	0.1873
1292	5e+12	NDD	92.819	92.686	-0.1327
1364	1e+13	NDD	91.21	91.326	0.1156
1383	5e+12	NDD	93.791	93.784	-0.0079
1388	5e+12	NDD	91.335	91.217	-0.1183
1427	1e+13	NDD	91.718	91.764	0.0462
1666	0	CORRELATION	93.618	93.581	-0.0377

Test Statistics (kHz)

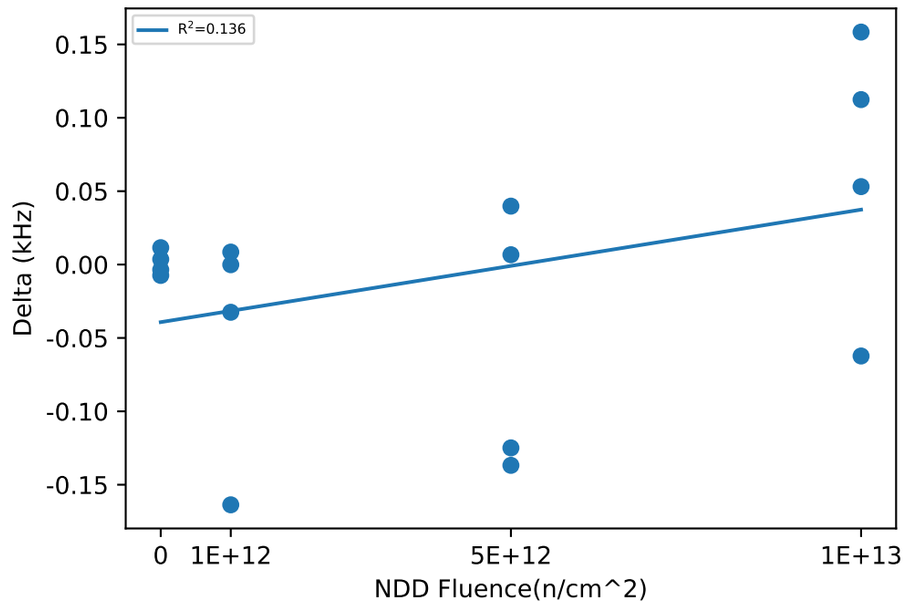
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.471	93.291	95.341	1.626	91.476	93.279	95.342	1.624	-0.0377	-0.01155	0.0049	0.019431
1e+12	90.9	92.764	94.003	1.3761	90.895	92.713	93.836	1.3292	-0.1671	-0.050525	-0.005	0.078113
5e+12	91.335	92.984	93.991	1.2129	91.217	92.923	94.004	1.275	-0.1327	-0.061525	0.0128	0.074586
1e+13	91.21	92.163	93.24	0.88859	91.326	92.233	93.427	0.91307	-0.0708	0.069575	0.1873	0.10989

Device Test: 20.77 LEVEL|FREQ/RT/14/14/0/1000/5/100kHz//@FSW_EXT_RT_A

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 80.0, Upper Limit = 110.0 (kHz))

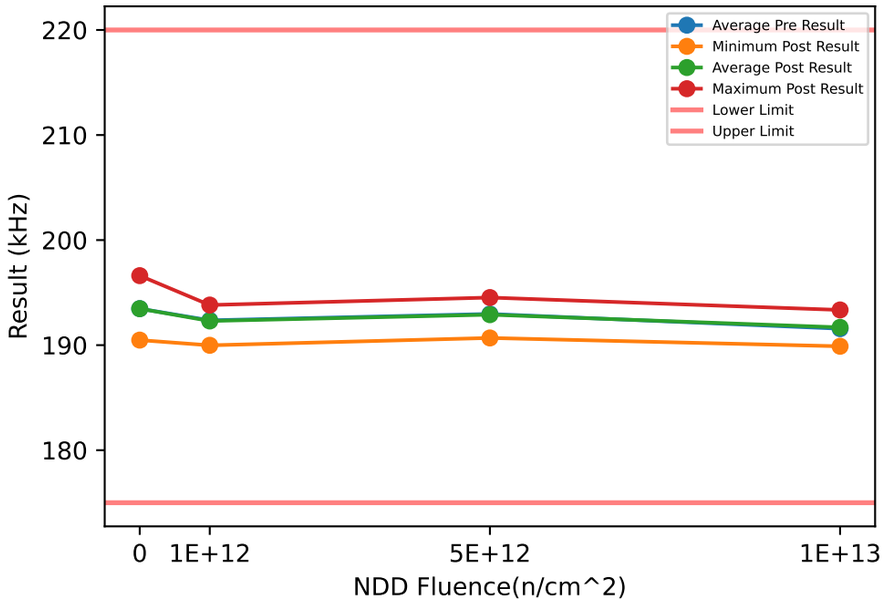
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	92.726	92.719	-0.0074
466	1e+12	NDD	93.549	93.549	-0.0001
762	0	CORRELATION	91.458	91.47	0.0115
769	1e+12	NDD	92.561	92.569	0.0085
887	1e+12	NDD	93.998	93.834	-0.1637
891	0	CORRELATION	95.329	95.333	0.0036
927	1e+12	NDD	90.907	90.874	-0.0325
967	5e+12	NDD	93.971	94.011	0.0398
1204	1e+13	NDD	92.474	92.412	-0.0623
1284	1e+13	NDD	93.25	93.408	0.1584
1292	5e+12	NDD	92.809	92.684	-0.1249
1364	1e+13	NDD	91.202	91.314	0.1124
1383	5e+12	NDD	93.765	93.772	0.0067
1388	5e+12	NDD	91.343	91.206	-0.1368
1427	1e+13	NDD	91.71	91.763	0.0531
1666	0	CORRELATION	93.581	93.578	-0.0035

Test Statistics (kHz)

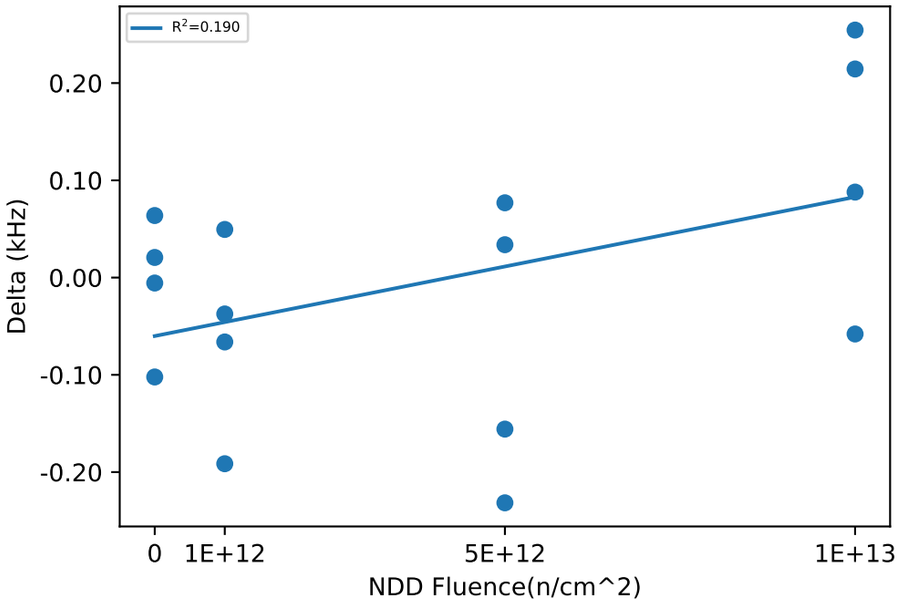
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	91.458	93.274	95.329	1.6242	91.47	93.275	95.333	1.6221	-0.0074	0.00105	0.0115	0.0083229
1e+12	90.907	92.753	93.998	1.3696	90.874	92.706	93.834	1.3362	-0.1637	-0.04695	0.0085	0.07981
5e+12	91.343	92.972	93.971	1.1984	91.206	92.918	94.011	1.2792	-0.1368	-0.0538	0.0398	0.090121
1e+13	91.202	92.159	93.25	0.89557	91.314	92.224	93.408	0.90867	-0.0623	0.0654	0.1584	0.095423

Device Test: 20.79 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

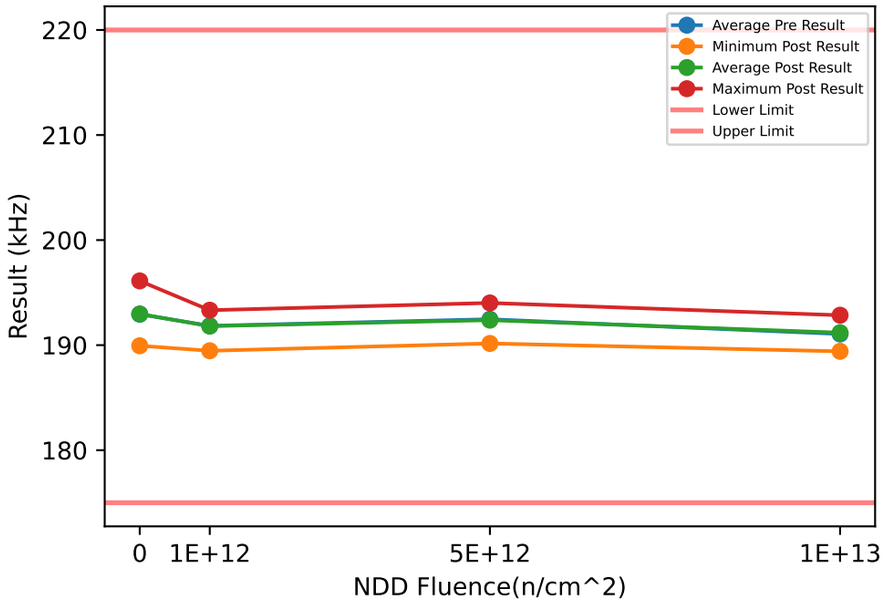
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.95	192.85	-0.1022
466	1e+12	NDD	193.3	193.26	-0.0374
762	0	CORRELATION	190.49	190.48	-0.0056
769	1e+12	NDD	192.09	192.14	0.0495
887	1e+12	NDD	194.01	193.82	-0.1914
891	0	CORRELATION	196.59	196.62	0.0207
927	1e+12	NDD	190.05	189.98	-0.0662
967	5e+12	NDD	194.45	194.53	0.0769
1204	1e+13	NDD	192.45	192.39	-0.058
1284	1e+13	NDD	193.1	193.35	0.2545
1292	5e+12	NDD	192.63	192.48	-0.1558
1364	1e+13	NDD	189.68	189.89	0.2145
1383	5e+12	NDD	193.87	193.91	0.0338
1388	5e+12	NDD	190.92	190.68	-0.2316
1427	1e+13	NDD	191.04	191.13	0.0879
1666	0	CORRELATION	193.87	193.93	0.0638

Test Statistics (kHz)

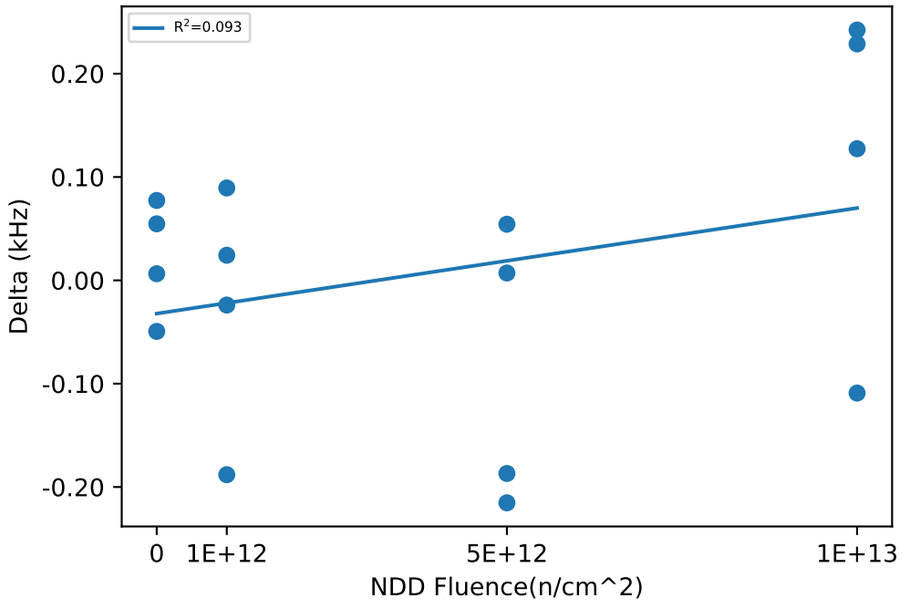
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	190.49	193.48	196.59	2.5229	190.48	193.47	196.62	2.5449	-0.1022	-0.005825	0.0638	0.070331
1e+12	190.05	192.36	194.01	1.7326	189.98	192.3	193.82	1.6946	-0.1914	-0.061375	0.0495	0.099663
5e+12	190.92	192.97	194.45	1.5652	190.68	192.9	194.53	1.7088	-0.2316	-0.069175	0.0769	0.14813
1e+13	189.68	191.57	193.1	1.5237	189.89	191.69	193.35	1.5052	-0.058	0.12472	0.2545	0.141

Device Test: 20.81 LEVEL|FREQ/RT/5/5/0/1000/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

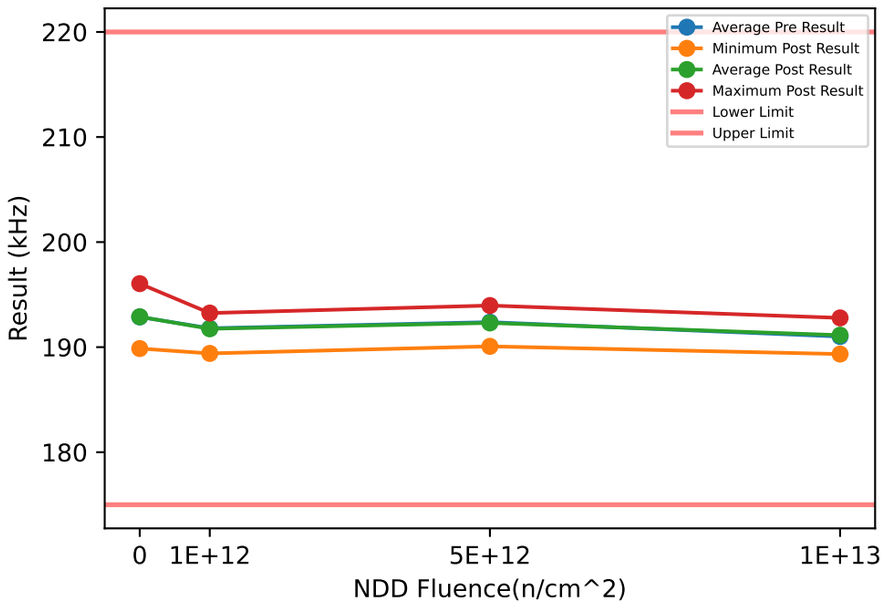
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.42	192.37	-0.0494
466	1e+12	NDD	192.8	192.82	0.0243
762	0	CORRELATION	189.93	189.94	0.0064
769	1e+12	NDD	191.54	191.63	0.0894
887	1e+12	NDD	193.51	193.33	-0.1881
891	0	CORRELATION	196.06	196.11	0.0547
927	1e+12	NDD	189.49	189.46	-0.0239
967	5e+12	NDD	193.96	194.02	0.0543
1204	1e+13	NDD	191.97	191.86	-0.1091
1284	1e+13	NDD	192.6	192.85	0.2422
1292	5e+12	NDD	192.11	191.93	-0.1869
1364	1e+13	NDD	189.18	189.41	0.2288
1383	5e+12	NDD	193.4	193.41	0.0071
1388	5e+12	NDD	190.38	190.16	-0.2153
1427	1e+13	NDD	190.5	190.62	0.1274
1666	0	CORRELATION	193.36	193.44	0.0773

Test Statistics (kHz)

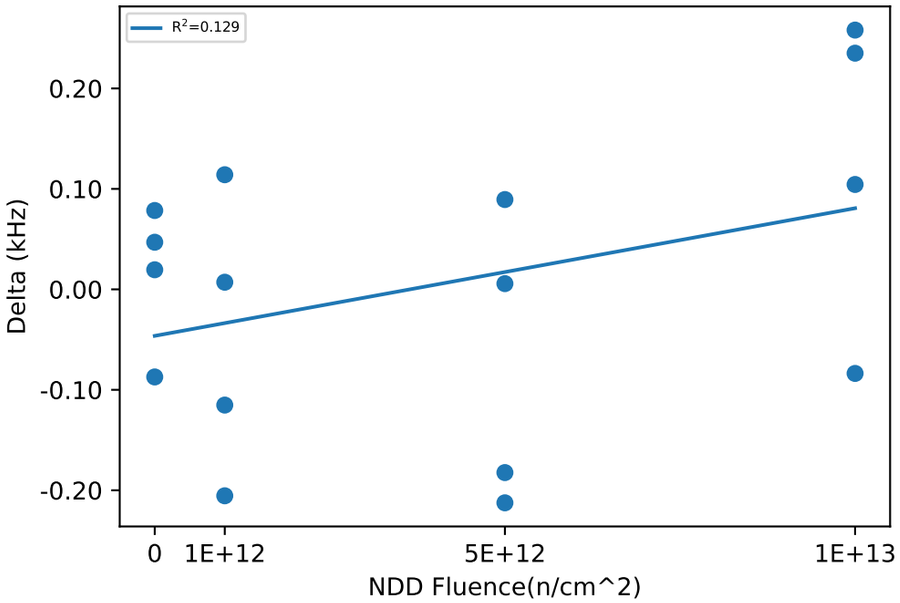
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.93	192.94	196.06	2.5304	189.94	192.97	196.11	2.5584	-0.0494	0.02225	0.0773	0.05618
1e+12	189.49	191.84	193.51	1.765	189.46	191.81	193.33	1.7188	-0.1881	-0.024575	0.0894	0.11849
5e+12	190.38	192.46	193.96	1.5927	190.16	192.38	194.02	1.7197	-0.2153	-0.0852	0.0543	0.13571
1e+13	189.18	191.06	192.6	1.534	189.41	191.19	192.85	1.4924	-0.1091	0.12233	0.2422	0.16257

Device Test: 20.83 LEVEL|FREQ/RT/12/12/0/1000/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

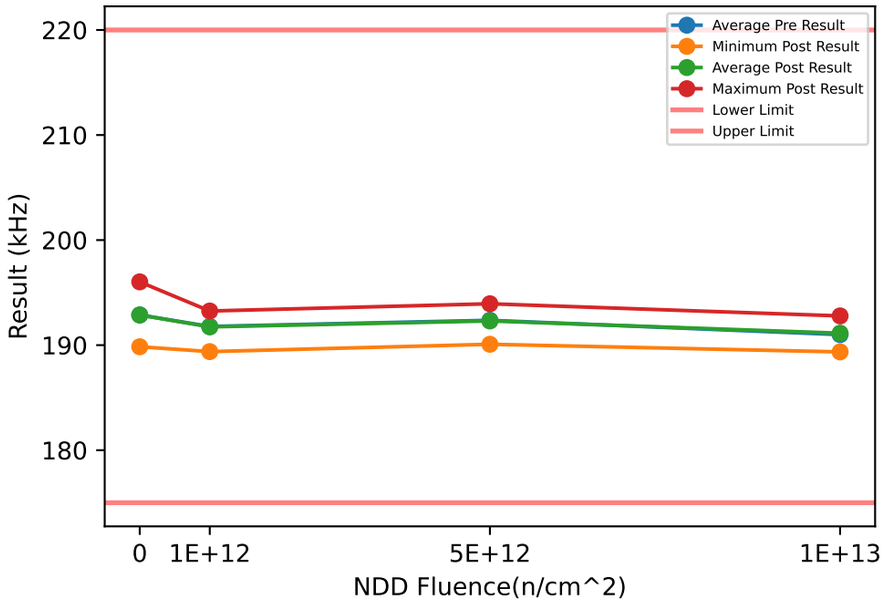
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.36	192.27	-0.0872
466	1e+12	NDD	192.75	192.76	0.0071
762	0	CORRELATION	189.85	189.87	0.0195
769	1e+12	NDD	191.47	191.58	0.1141
887	1e+12	NDD	193.45	193.24	-0.2055
891	0	CORRELATION	196	196.04	0.0469
927	1e+12	NDD	189.52	189.4	-0.1152
967	5e+12	NDD	193.87	193.96	0.0894
1204	1e+13	NDD	191.93	191.85	-0.0837
1284	1e+13	NDD	192.53	192.78	0.2581
1292	5e+12	NDD	192.03	191.85	-0.1824
1364	1e+13	NDD	189.11	189.34	0.2351
1383	5e+12	NDD	193.33	193.33	0.0057
1388	5e+12	NDD	190.29	190.07	-0.2125
1427	1e+13	NDD	190.48	190.58	0.1044
1666	0	CORRELATION	193.29	193.37	0.0785

Test Statistics (kHz)

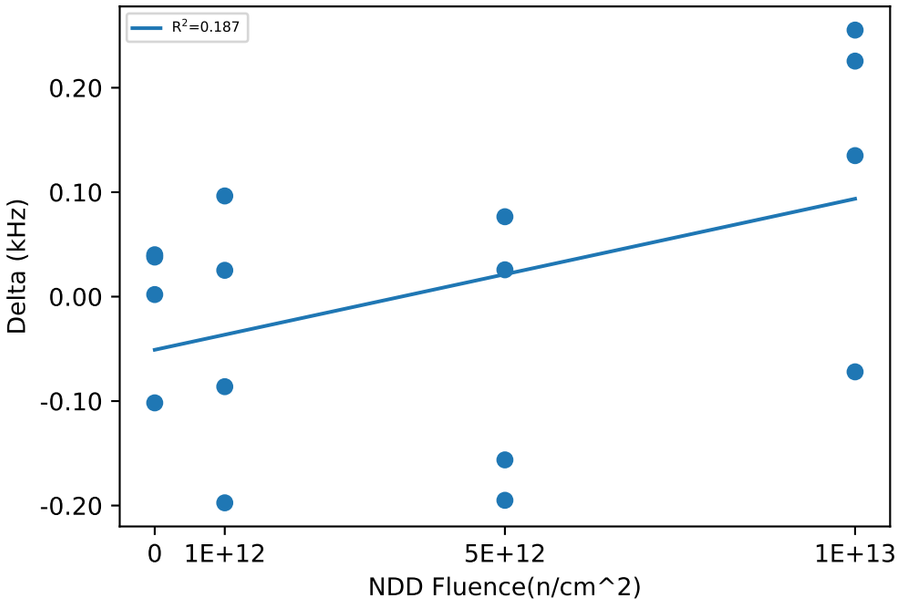
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.85	192.87	196	2.5401	189.87	192.89	196.04	2.5627	-0.0872	0.014425	0.0785	0.071911
1e+12	189.52	191.8	193.45	1.7265	189.4	191.75	193.24	1.7113	-0.2055	-0.049875	0.1141	0.13979
5e+12	190.29	192.38	193.87	1.5933	190.07	192.3	193.96	1.7295	-0.2125	-0.07495	0.0894	0.14604
1e+13	189.11	191.01	192.53	1.5329	189.34	191.14	192.78	1.4994	-0.0837	0.12848	0.2581	0.15681

Device Test: 20.85 LEVEL|FREQ/RT/14/14/0/1000/5/200kHz//@FSW_EXT_RT_B

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 175.0, Upper Limit = 220.0 (kHz))

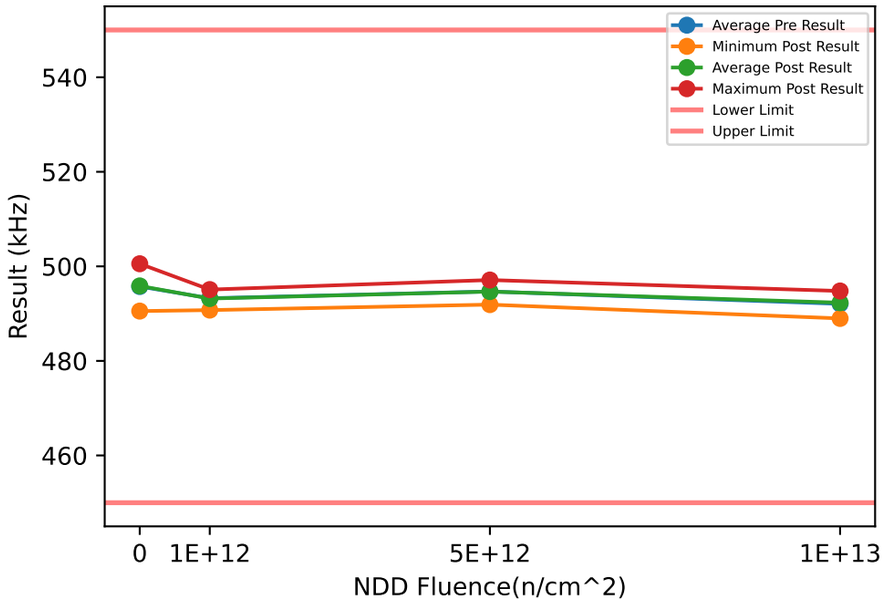
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	192.37	192.27	-0.1017
466	1e+12	NDD	192.72	192.75	0.0252
762	0	CORRELATION	189.85	189.85	0.002
769	1e+12	NDD	191.48	191.57	0.0964
887	1e+12	NDD	193.45	193.25	-0.1974
891	0	CORRELATION	195.98	196.02	0.0401
927	1e+12	NDD	189.47	189.38	-0.0862
967	5e+12	NDD	193.86	193.94	0.0765
1204	1e+13	NDD	191.9	191.83	-0.072
1284	1e+13	NDD	192.56	192.78	0.2255
1292	5e+12	NDD	192.01	191.86	-0.1563
1364	1e+13	NDD	189.1	189.36	0.2552
1383	5e+12	NDD	193.31	193.33	0.0257
1388	5e+12	NDD	190.28	190.08	-0.195
1427	1e+13	NDD	190.44	190.58	0.135
1666	0	CORRELATION	193.3	193.34	0.0379

Test Statistics (kHz)

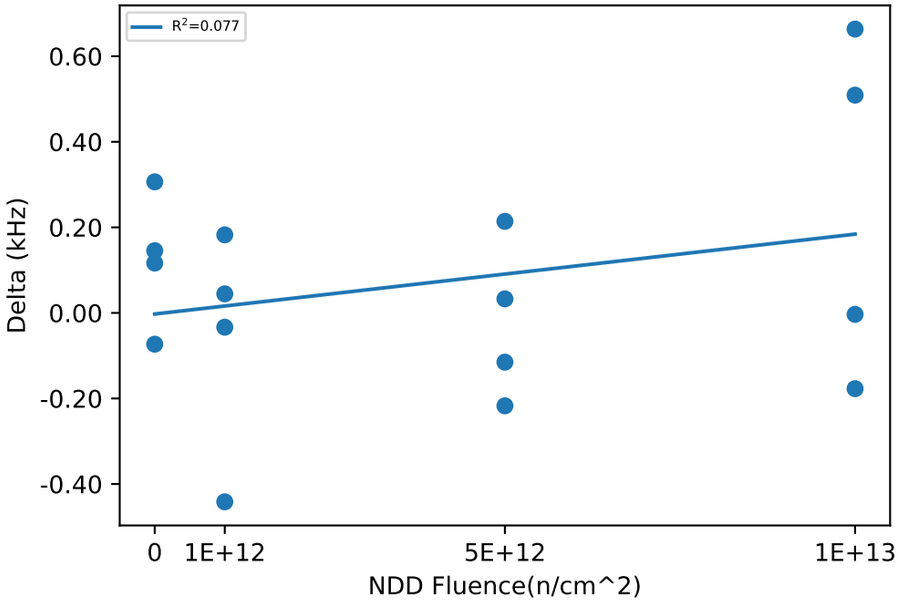
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	189.85	192.87	195.98	2.5348	189.85	192.87	196.02	2.5601	-0.1017	-0.005425	0.0401	0.066517
1e+12	189.47	191.78	193.45	1.7409	189.38	191.74	193.25	1.7197	-0.1974	-0.0405	0.0964	0.12879
5e+12	190.28	192.36	193.86	1.5925	190.08	192.3	193.94	1.7188	-0.195	-0.062275	0.0765	0.13348
1e+13	189.1	191	192.56	1.543	189.36	191.14	192.78	1.4901	-0.072	0.13593	0.2552	0.14774

Device Test: 20.87 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

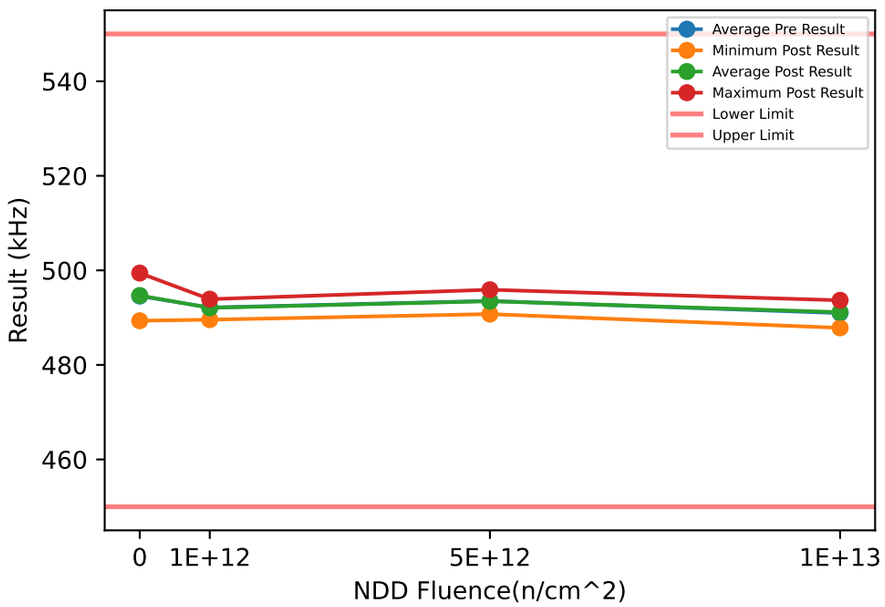
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	495.4	495.71	0.3064
466	1e+12	NDD	493.67	493.71	0.0445
762	0	CORRELATION	490.42	490.54	0.1165
769	1e+12	NDD	493.25	493.22	-0.0334
887	1e+12	NDD	495.53	495.08	-0.4416
891	0	CORRELATION	500.4	500.55	0.1455
927	1e+12	NDD	490.56	490.75	0.1825
967	5e+12	NDD	497.32	497.11	-0.2172
1204	1e+13	NDD	494.79	494.79	-0.0034
1284	1e+13	NDD	493.45	493.95	0.5091
1292	5e+12	NDD	493.73	493.62	-0.1151
1364	1e+13	NDD	488.32	488.98	0.6635
1383	5e+12	NDD	495.8	496.02	0.214
1388	5e+12	NDD	491.87	491.91	0.0328
1427	1e+13	NDD	491.7	491.52	-0.1771
1666	0	CORRELATION	496.72	496.65	-0.0731

Test Statistics (kHz)

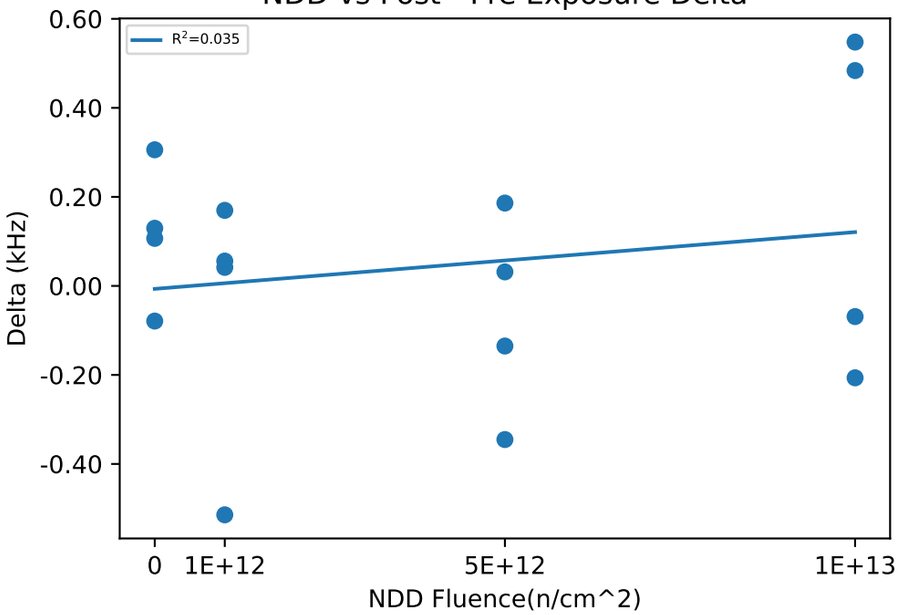
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	490.42	495.74	500.4	4.1279	490.54	495.86	500.55	4.1216	-0.0731	0.12383	0.3064	0.1556
1e+12	490.56	493.25	495.53	2.0475	490.75	493.19	495.08	1.811	-0.4416	-0.062	0.1825	0.26835
5e+12	491.87	494.68	497.32	2.3826	491.91	494.66	497.11	2.3455	-0.2172	-0.021375	0.214	0.1875
1e+13	488.32	492.06	494.79	2.7995	488.98	492.31	494.79	2.6171	-0.1771	0.24802	0.6635	0.40196

Device Test: 20.89 LEVEL|FREQ/RT/5/5/0/1000/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

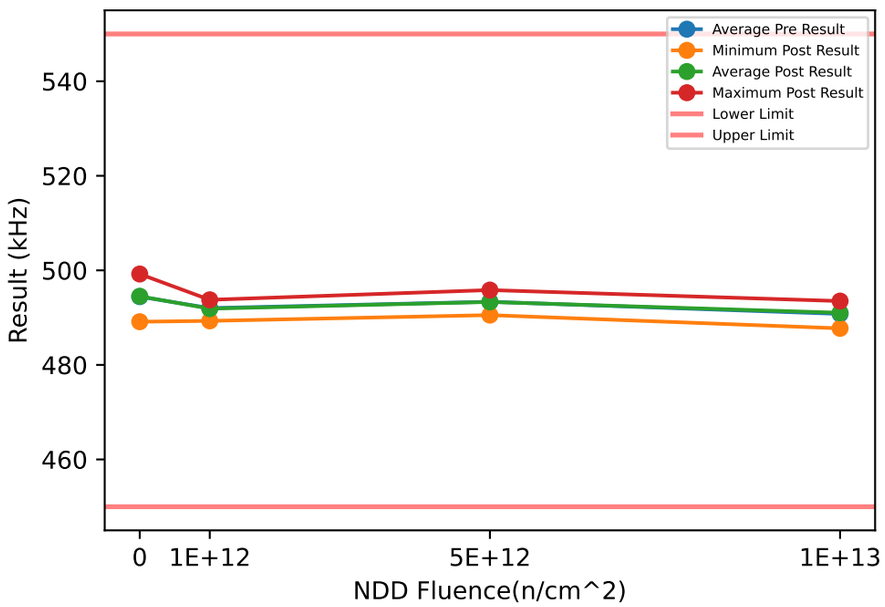
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	494.21	494.51	0.3058
466	1e+12	NDD	492.65	492.69	0.0416
762	0	CORRELATION	489.21	489.34	0.1295
769	1e+12	NDD	492.07	492.13	0.0558
887	1e+12	NDD	494.42	493.9	-0.5143
891	0	CORRELATION	499.31	499.42	0.1068
927	1e+12	NDD	489.39	489.56	0.1697
967	5e+12	NDD	496.24	495.9	-0.3452
1204	1e+13	NDD	493.73	493.66	-0.0689
1284	1e+13	NDD	492.3	492.78	0.4838
1292	5e+12	NDD	492.51	492.37	-0.1351
1364	1e+13	NDD	487.29	487.84	0.5478
1383	5e+12	NDD	494.66	494.85	0.1861
1388	5e+12	NDD	490.72	490.75	0.0315
1427	1e+13	NDD	490.55	490.34	-0.2065
1666	0	CORRELATION	495.54	495.46	-0.079

Test Statistics (kHz)

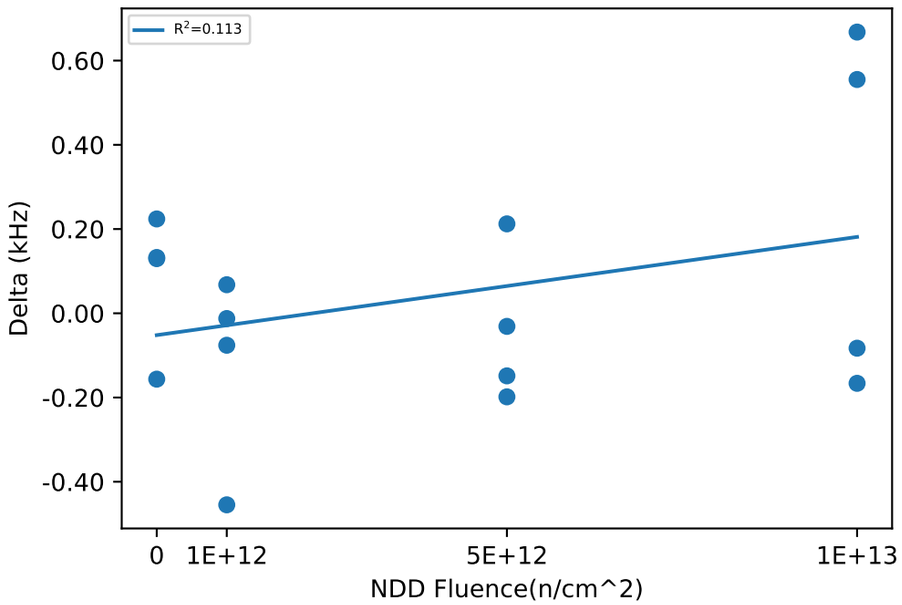
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	489.21	494.57	499.31	4.1761	489.34	494.68	499.42	4.1491	-0.079	0.11577	0.3058	0.15739
1e+12	489.39	492.13	494.42	2.0816	489.56	492.07	493.9	1.8293	-0.5143	-0.0618	0.1697	0.30707
5e+12	490.72	493.53	496.24	2.4222	490.75	493.47	495.9	2.3384	-0.3452	-0.065675	0.1861	0.22788
1e+13	487.29	490.97	493.73	2.7762	487.84	491.16	493.66	2.6209	-0.2065	0.18905	0.5478	0.38235

Device Test: 20.91 LEVEL|FREQ/RT/12/12/0/1000/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

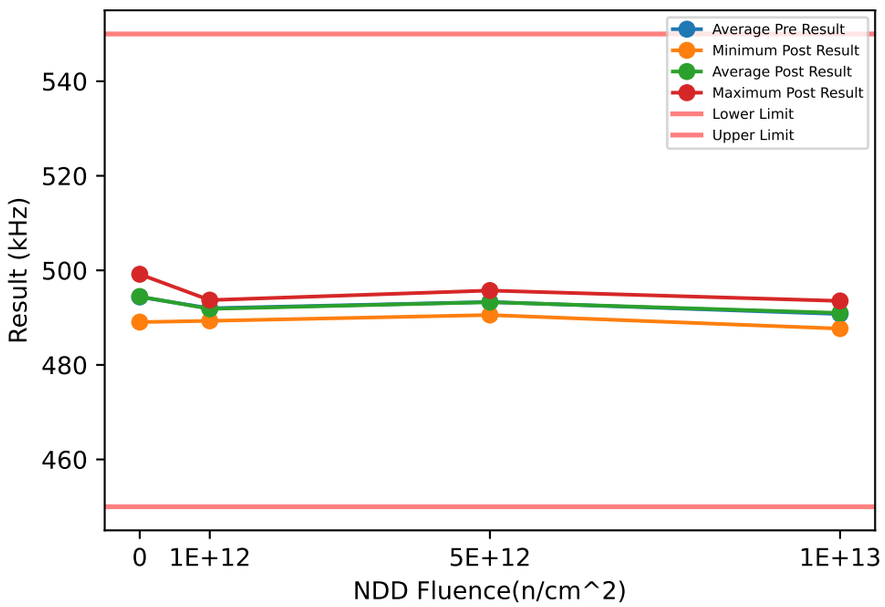
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	494.19	494.42	0.224
466	1e+12	NDD	492.5	492.57	0.0678
762	0	CORRELATION	489	489.13	0.1325
769	1e+12	NDD	491.94	491.93	-0.0125
887	1e+12	NDD	494.22	493.77	-0.4548
891	0	CORRELATION	499.09	499.22	0.1297
927	1e+12	NDD	489.39	489.31	-0.0759
967	5e+12	NDD	496.03	495.83	-0.1984
1204	1e+13	NDD	493.58	493.5	-0.0829
1284	1e+13	NDD	492.07	492.63	0.5551
1292	5e+12	NDD	492.32	492.18	-0.1486
1364	1e+13	NDD	487.07	487.73	0.6677
1383	5e+12	NDD	494.5	494.71	0.2123
1388	5e+12	NDD	490.56	490.53	-0.0311
1427	1e+13	NDD	490.41	490.25	-0.1663
1666	0	CORRELATION	495.44	495.29	-0.1564

Test Statistics (kHz)

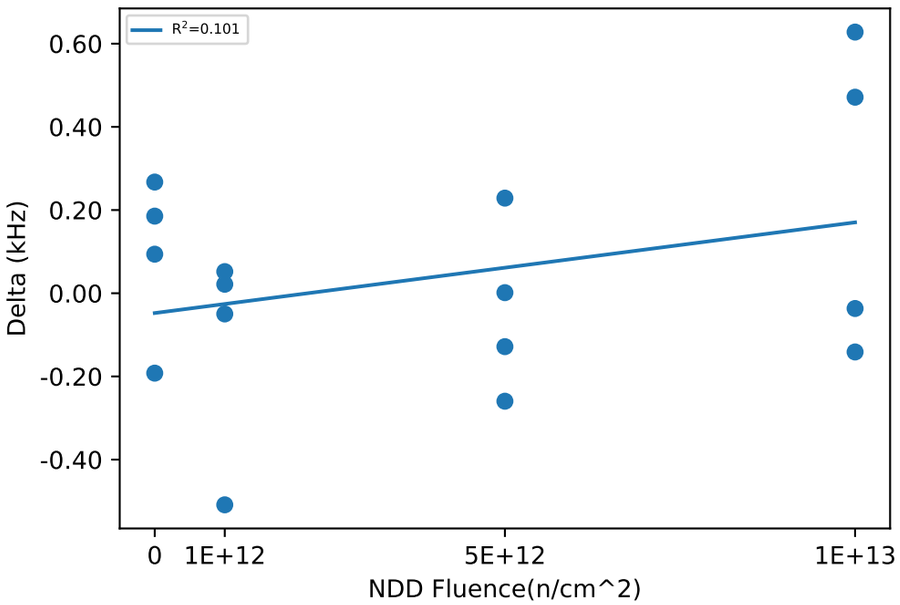
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	489	494.43	499.09	4.175	489.13	494.52	499.22	4.1521	-0.1564	0.08245	0.224	0.16515
1e+12	489.39	492.01	494.22	2.0022	489.31	491.89	493.77	1.8837	-0.4548	-0.11885	0.0678	0.23156
5e+12	490.56	493.35	496.03	2.4017	490.53	493.31	495.83	2.4022	-0.1984	-0.04145	0.2123	0.18313
1e+13	487.07	490.78	493.58	2.7972	487.73	491.03	493.5	2.5916	-0.1663	0.2434	0.6677	0.42876

Device Test: 20.93 LEVEL|FREQ/RT/14/14/0/1000/5/500kHz//@FSW_EXT_RT_C

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 450.0, Upper Limit = 550.0 (kHz))

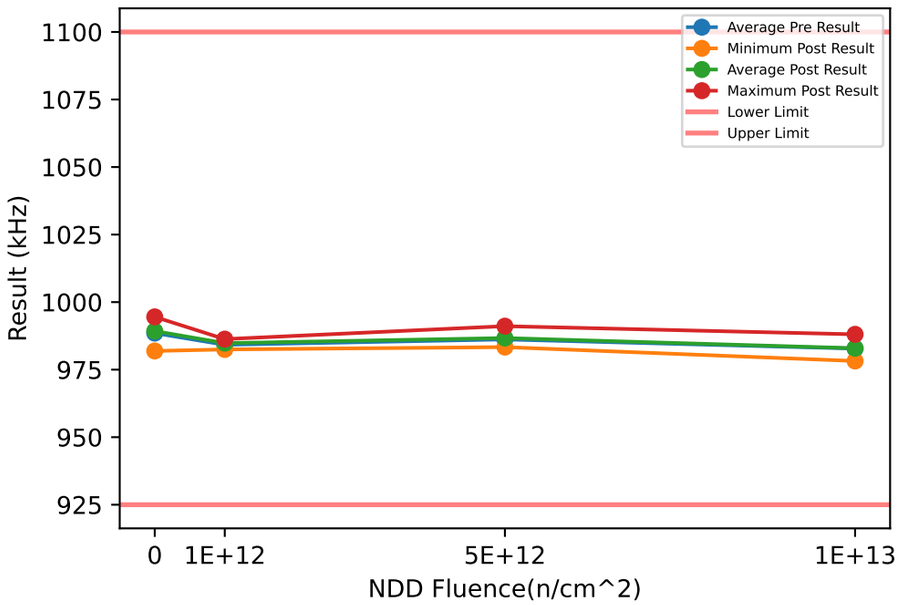
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	494.11	494.37	0.2673
466	1e+12	NDD	492.48	492.5	0.0216
762	0	CORRELATION	488.96	489.06	0.0939
769	1e+12	NDD	491.94	491.89	-0.0498
887	1e+12	NDD	494.21	493.71	-0.5087
891	0	CORRELATION	498.99	499.18	0.1854
927	1e+12	NDD	489.26	489.31	0.052
967	5e+12	NDD	495.99	495.73	-0.2596
1204	1e+13	NDD	493.57	493.53	-0.0367
1284	1e+13	NDD	492.07	492.55	0.4713
1292	5e+12	NDD	492.27	492.15	-0.1284
1364	1e+13	NDD	487.04	487.67	0.6279
1383	5e+12	NDD	494.42	494.64	0.2287
1388	5e+12	NDD	490.55	490.55	0.0014
1427	1e+13	NDD	490.35	490.21	-0.1412
1666	0	CORRELATION	495.43	495.24	-0.1921

Test Statistics (kHz)

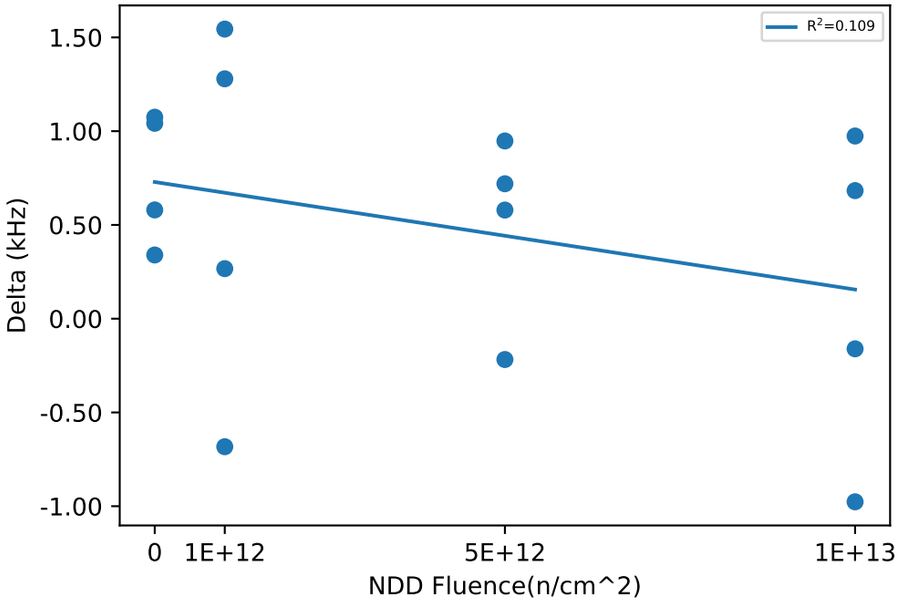
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	488.96	494.37	498.99	4.1546	489.06	494.46	499.18	4.1654	-0.1921	0.088625	0.2673	0.2001
1e+12	489.26	491.98	494.21	2.0525	489.31	491.85	493.71	1.8536	-0.5087	-0.12122	0.052	0.26182
5e+12	490.55	493.31	495.99	2.3857	490.55	493.27	495.73	2.3507	-0.2596	-0.039475	0.2287	0.20813
1e+13	487.04	490.76	493.57	2.8038	487.67	490.99	493.53	2.6136	-0.1412	0.23032	0.6279	0.37659

Device Test: 20.95 LEVEL|FREQ/RT/4.5/4.5/0/1000/4.5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

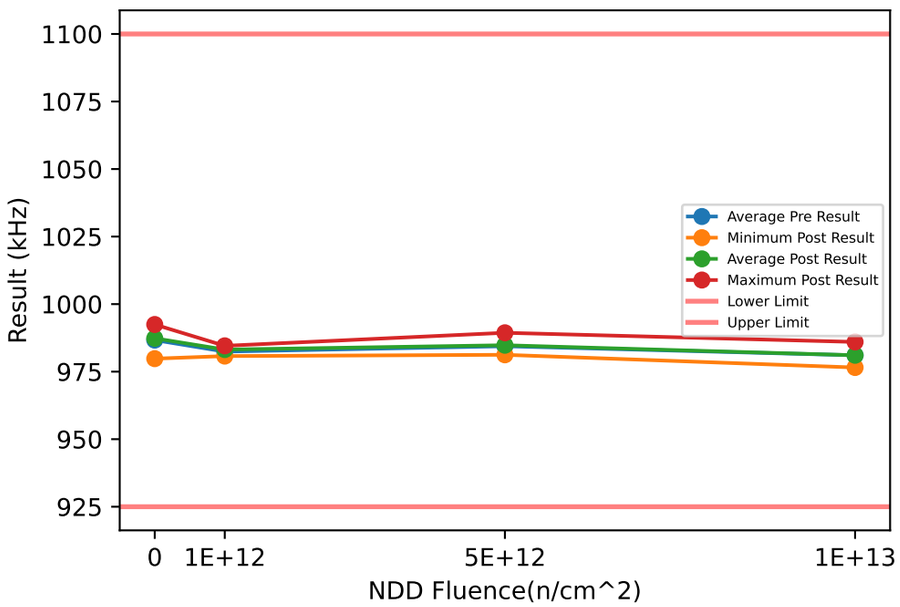
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	989.23	989.57	0.3397
466	1e+12	NDD	984.19	984.45	0.2669
762	0	CORRELATION	981.33	981.91	0.5799
769	1e+12	NDD	985.02	986.3	1.2792
887	1e+12	NDD	986.69	986.01	-0.6827
891	0	CORRELATION	993.47	994.54	1.0745
927	1e+12	NDD	980.94	982.48	1.5444
967	5e+12	NDD	990.15	991.1	0.9477
1204	1e+13	NDD	988.24	988.08	-0.1607
1284	1e+13	NDD	983	982.03	-0.9766
1292	5e+12	NDD	983.82	984.54	0.7195
1364	1e+13	NDD	977.52	978.2	0.6829
1383	5e+12	NDD	987.24	987.82	0.5793
1388	5e+12	NDD	983.56	983.34	-0.2178
1427	1e+13	NDD	982.45	983.42	0.9741
1666	0	CORRELATION	990.08	991.12	1.042

Test Statistics (kHz)

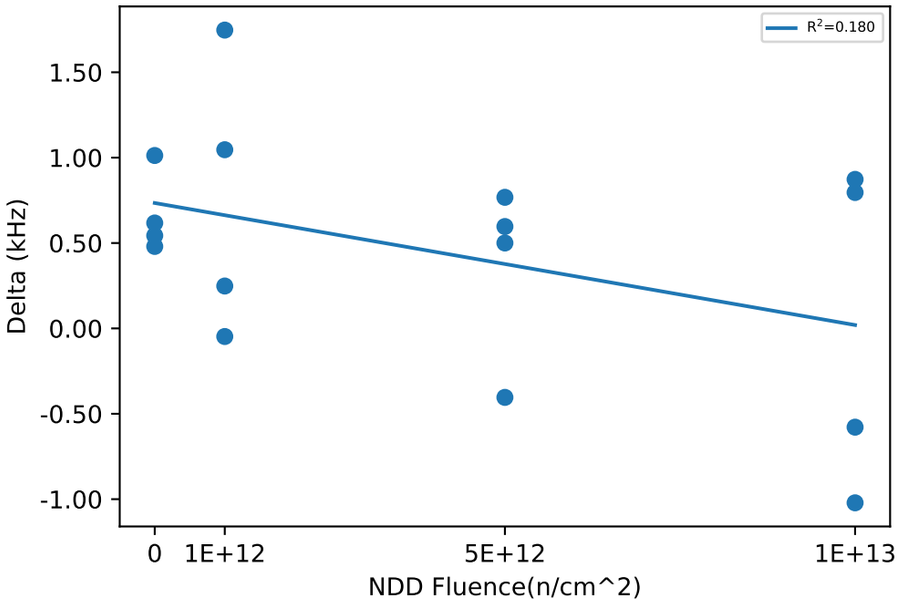
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	981.33	988.53	993.47	5.132	981.91	989.28	994.54	5.3349	0.3397	0.75902	1.0745	0.35941
1e+12	980.94	984.21	986.69	2.4164	982.48	984.81	986.3	1.7521	-0.6827	0.60195	1.5444	1.0181
5e+12	983.56	986.2	990.15	3.1252	983.34	986.7	991.1	3.4889	-0.2178	0.50718	0.9477	0.5066
1e+13	977.52	982.8	988.24	4.3833	978.2	982.93	988.08	4.0793	-0.9766	0.12992	0.9741	0.88077

Device Test: 20.97 LEVEL|FREQ/RT/5/5/0/1000/5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

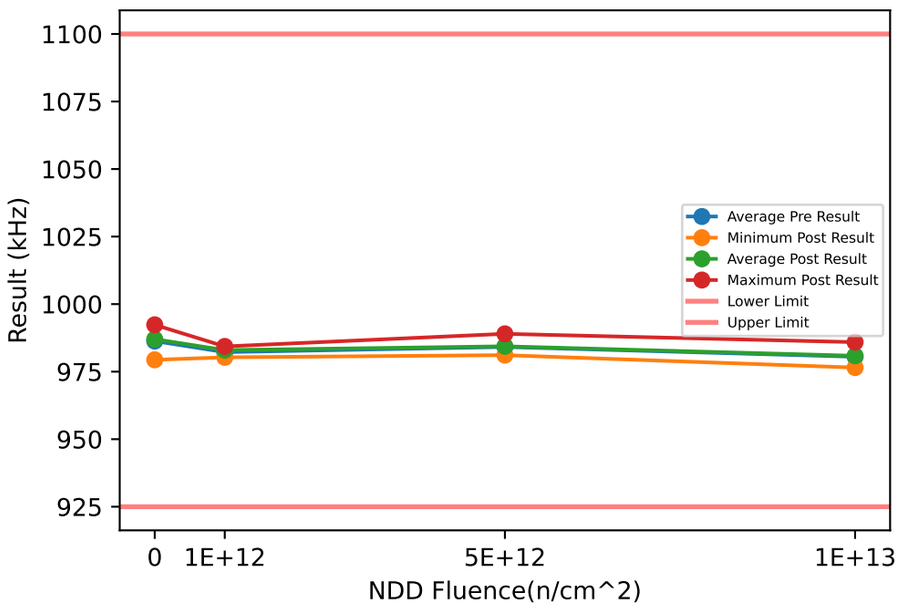
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	987.22	987.7	0.4801
466	1e+12	NDD	982.67	982.92	0.2482
762	0	CORRELATION	979.27	979.81	0.5434
769	1e+12	NDD	983.39	984.44	1.0464
887	1e+12	NDD	984.61	984.56	-0.0475
891	0	CORRELATION	991.84	992.45	0.6173
927	1e+12	NDD	979.02	980.76	1.7471
967	5e+12	NDD	988.62	989.39	0.7677
1204	1e+13	NDD	986.58	986	-0.5784
1284	1e+13	NDD	981.34	980.32	-1.0214
1292	5e+12	NDD	982.11	982.71	0.5966
1364	1e+13	NDD	975.74	976.54	0.7959
1383	5e+12	NDD	985.3	985.8	0.5002
1388	5e+12	NDD	981.64	981.24	-0.404
1427	1e+13	NDD	980.55	981.42	0.8727
1666	0	CORRELATION	988.4	989.41	1.0126

Test Statistics (kHz)

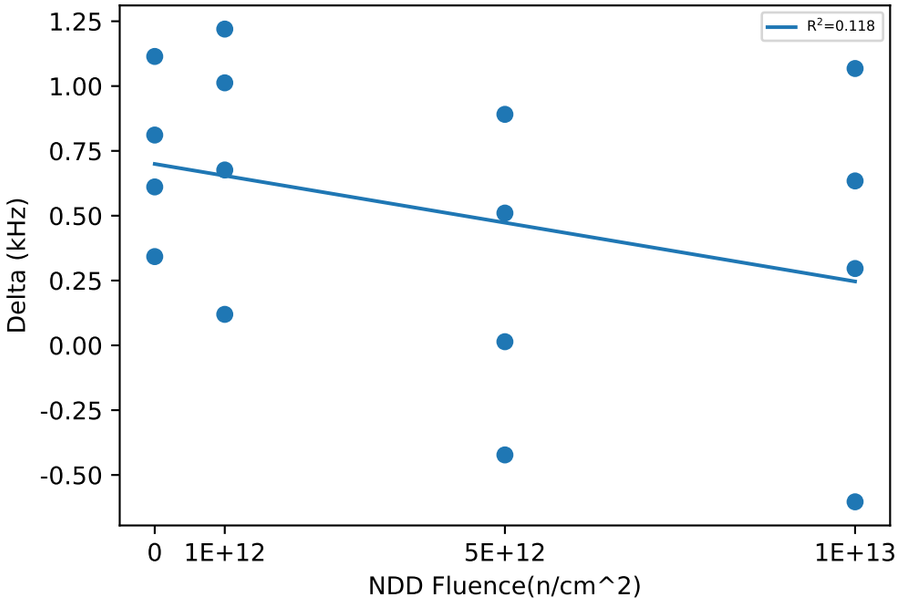
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	979.27	986.68	991.84	5.317	979.81	987.34	992.45	5.3941	0.4801	0.66335	1.0126	0.23949
1e+12	979.02	982.42	984.61	2.4068	980.76	983.17	984.56	1.7698	-0.0475	0.74855	1.7471	0.81032
5e+12	981.64	984.42	988.62	3.2378	981.24	984.78	989.39	3.61	-0.404	0.36512	0.7677	0.52455
1e+13	975.74	981.05	986.58	4.4383	976.54	981.07	986	3.8964	-1.0214	0.0172	0.8727	0.96119

Device Test: 20.99 LEVEL|FREQ/RT/12/12/0/1000/5/1MHz//@FSW_EXT_RT_D

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 925.0, Upper Limit = 1100.0 (kHz))

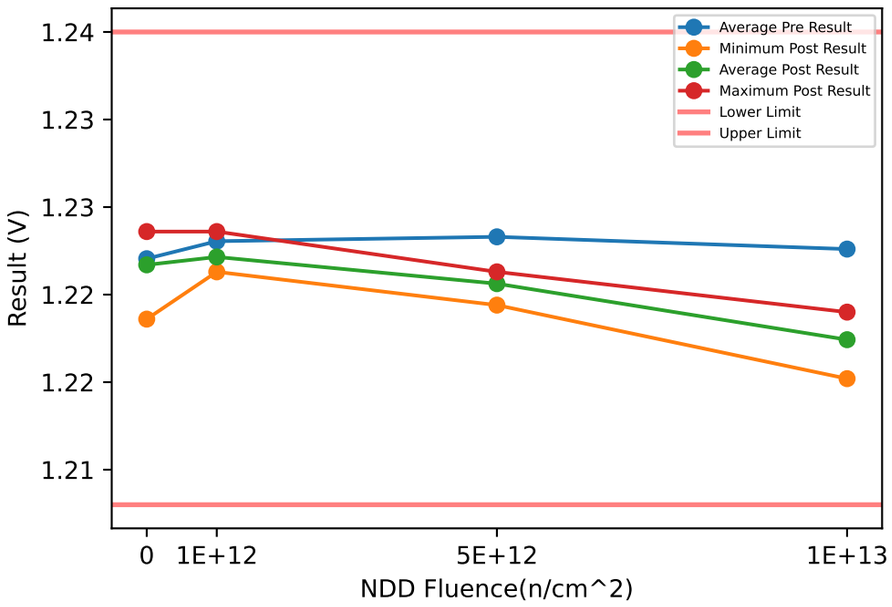
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	986.9	987.24	0.3423
466	1e+12	NDD	982.31	982.98	0.6763
762	0	CORRELATION	978.76	979.38	0.611
769	1e+12	NDD	983.11	984.33	1.2198
887	1e+12	NDD	984.18	984.3	0.1195
891	0	CORRELATION	991.53	992.34	0.8111
927	1e+12	NDD	979.29	980.3	1.0125
967	5e+12	NDD	988.49	989	0.5101
1204	1e+13	NDD	985.62	985.92	0.2963
1284	1e+13	NDD	980.53	979.93	-0.6035
1292	5e+12	NDD	981.74	982.63	0.8909
1364	1e+13	NDD	975.44	976.5	1.0677
1383	5e+12	NDD	984.77	984.78	0.014
1388	5e+12	NDD	981.54	981.11	-0.4226
1427	1e+13	NDD	980.51	981.14	0.6341
1666	0	CORRELATION	988.05	989.17	1.1142

Test Statistics (kHz)

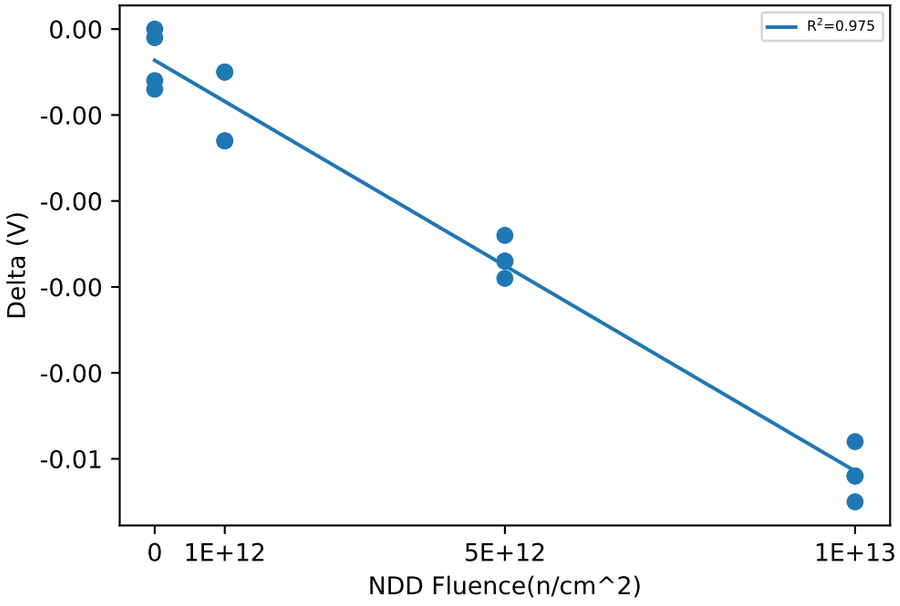
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	978.76	986.31	991.53	5.4033	979.38	987.03	992.34	5.5206	0.3423	0.71965	1.1142	0.32569
1e+12	979.29	982.22	984.18	2.0995	980.3	982.98	984.33	1.8918	0.1195	0.75702	1.2198	0.48041
5e+12	981.54	984.13	988.49	3.2578	981.11	984.38	989	3.4263	-0.4226	0.2481	0.8909	0.57343
1e+13	975.44	980.52	985.62	4.1595	976.5	980.87	985.92	3.8961	-0.6035	0.34865	1.0677	0.70895

Device Test: 21.1 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

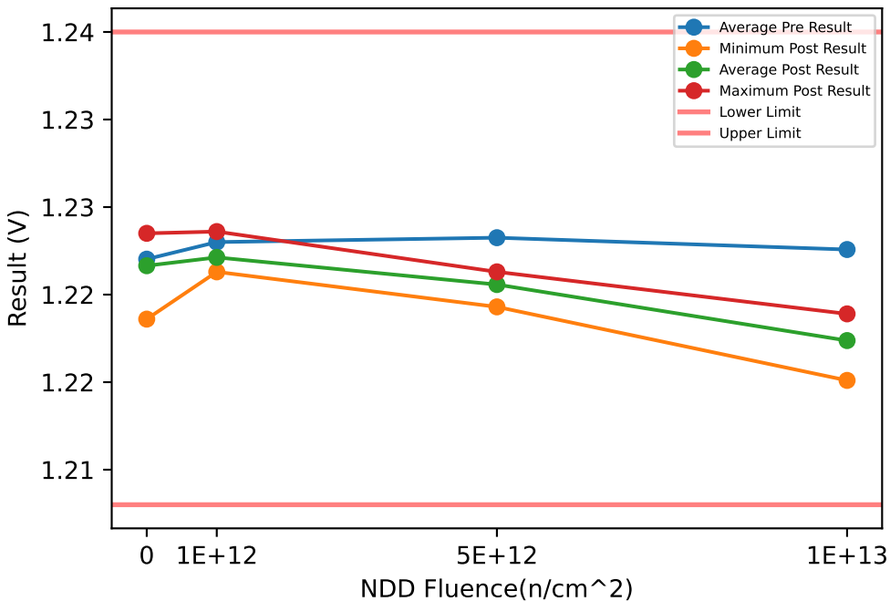
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2236	1.2209	-0.0027
1204	1e+13	NDD	1.2238	1.219	-0.0048
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

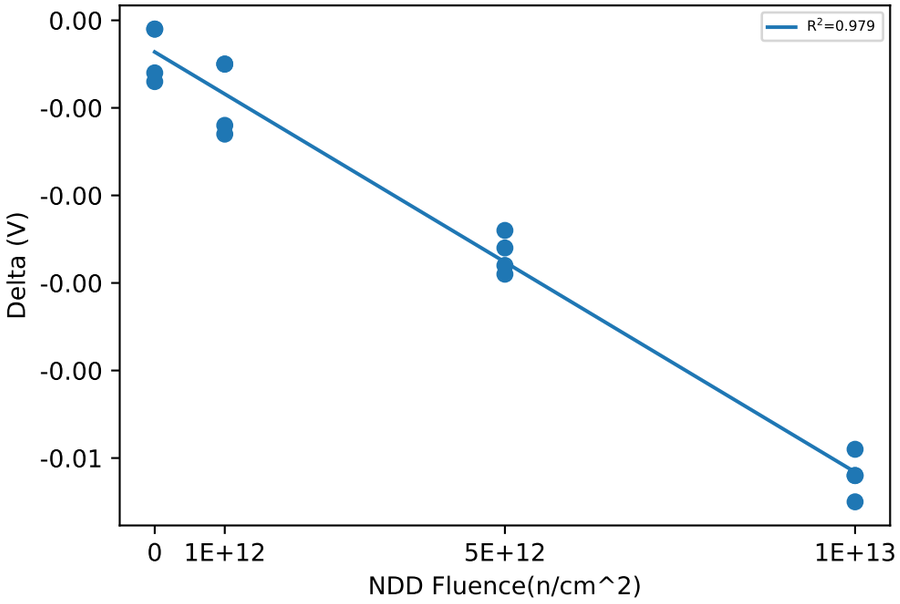
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0021063	1.2186	1.2217	1.2236	0.0022524	-0.0007	-0.00035	0	0.00035119
1e+12	1.2225	1.223	1.2241	0.00073258	1.2213	1.2222	1.2236	0.0010083	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2221	1.2233	1.2242	0.00088318	1.2194	1.2206	1.2213	0.00083815	-0.0029	-0.002675	-0.0024	0.00020616
1e+13	1.2204	1.2226	1.2238	0.0015578	1.2152	1.2174	1.219	0.0016215	-0.0055	-0.005175	-0.0048	0.00028723

Device Test: 21.11 VOLTAGE|VREF/VREF/5/5/0/0/5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

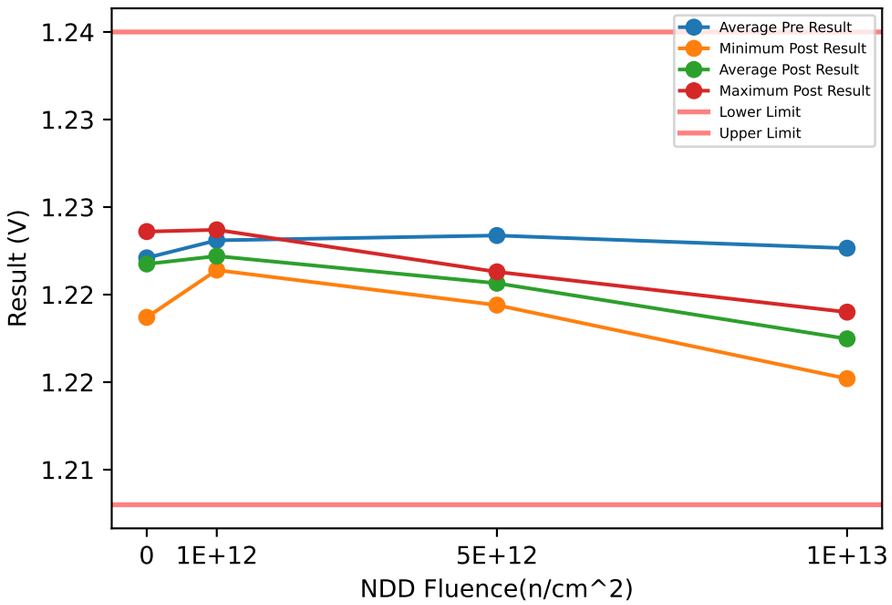
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2225	1.2213	-0.0012
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2238	1.2189	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2232	1.2208	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

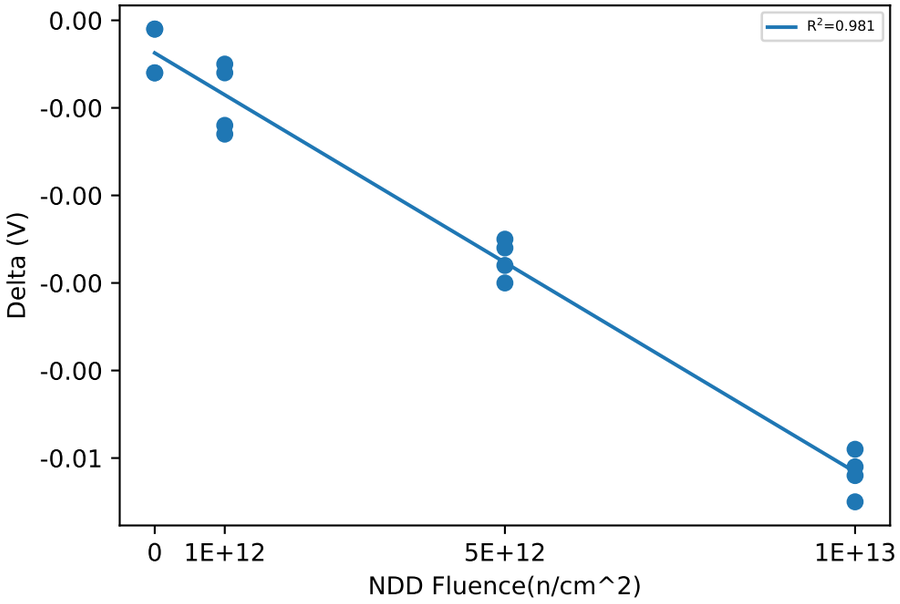
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.222	1.2237	0.0020807	1.2186	1.2216	1.2235	0.0022279	-0.0007	-0.000375	-0.0001	0.00032016
1e+12	1.2225	1.223	1.2241	0.00075719	1.2213	1.2221	1.2236	0.0010243	-0.0013	-0.000875	-0.0005	0.00043493
5e+12	1.2221	1.2232	1.2242	0.00087369	1.2193	1.2206	1.2213	0.00087702	-0.0029	-0.002675	-0.0024	0.00022174
1e+13	1.2203	1.2226	1.2238	0.0016049	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.13 VOLTAGE|VREF/VREF/12/12/0/0/5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

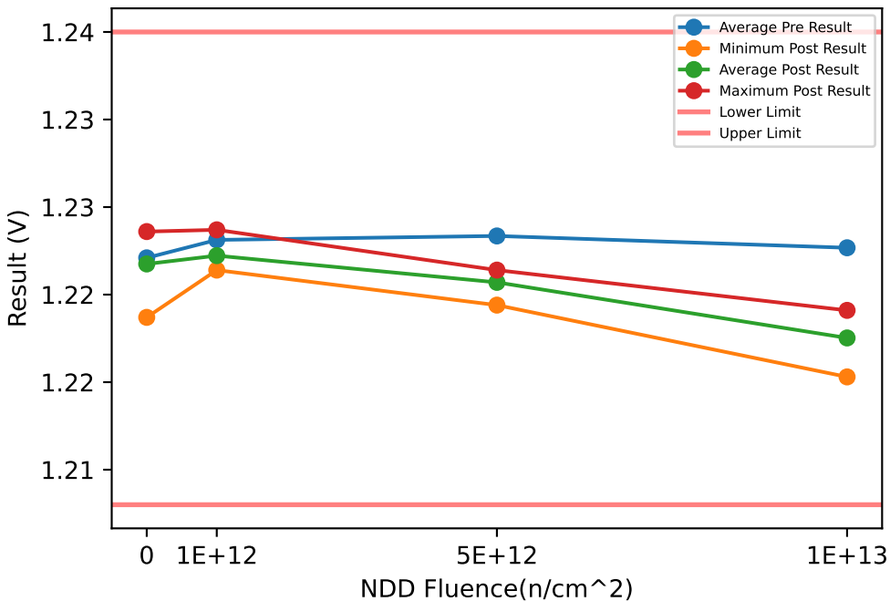
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2187	-0.0006
466	1e+12	NDD	1.2226	1.2214	-0.0012
762	0	CORRELATION	1.2238	1.2232	-0.0006
769	1e+12	NDD	1.2226	1.222	-0.0006
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2236	1.221	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2237	1.2182	-0.0055
1292	5e+12	NDD	1.2234	1.2209	-0.0025
1364	1e+13	NDD	1.2226	1.2175	-0.0051
1383	5e+12	NDD	1.2222	1.2194	-0.0028
1388	5e+12	NDD	1.2243	1.2213	-0.003
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

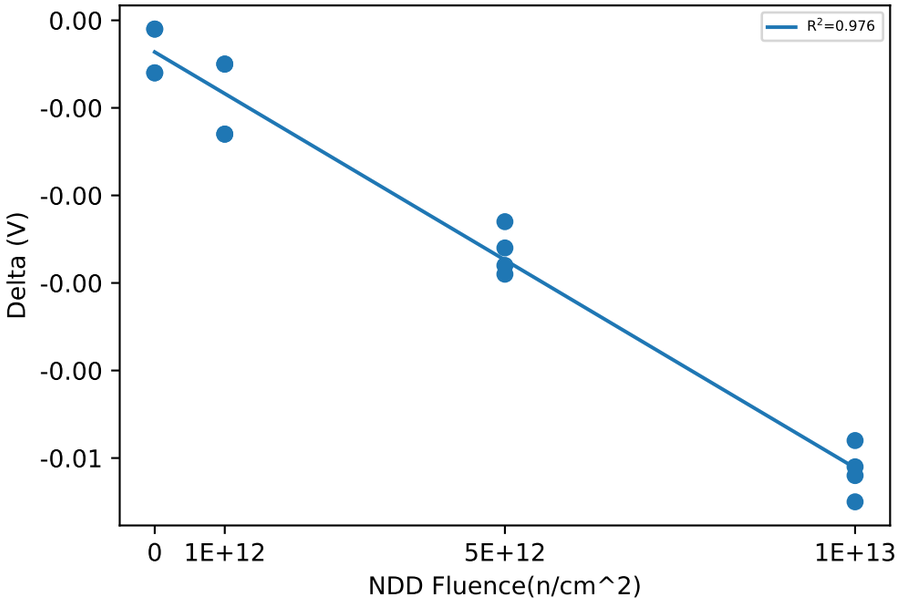
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2238	0.0021245	1.2187	1.2218	1.2236	0.0022279	-0.0006	-0.00035	-0.0001	0.00028868
1e+12	1.2226	1.2231	1.2242	0.00075719	1.2214	1.2222	1.2237	0.0010296	-0.0013	-0.0009	-0.0005	0.00040825
5e+12	1.2222	1.2234	1.2243	0.00087321	1.2194	1.2207	1.2213	0.00085049	-0.003	-0.002725	-0.0025	0.00022174
1e+13	1.2204	1.2227	1.2239	0.0016052	1.2152	1.2175	1.219	0.0016358	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.15 VOLTAGE|VREF/VREF/14/14/0/0/5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

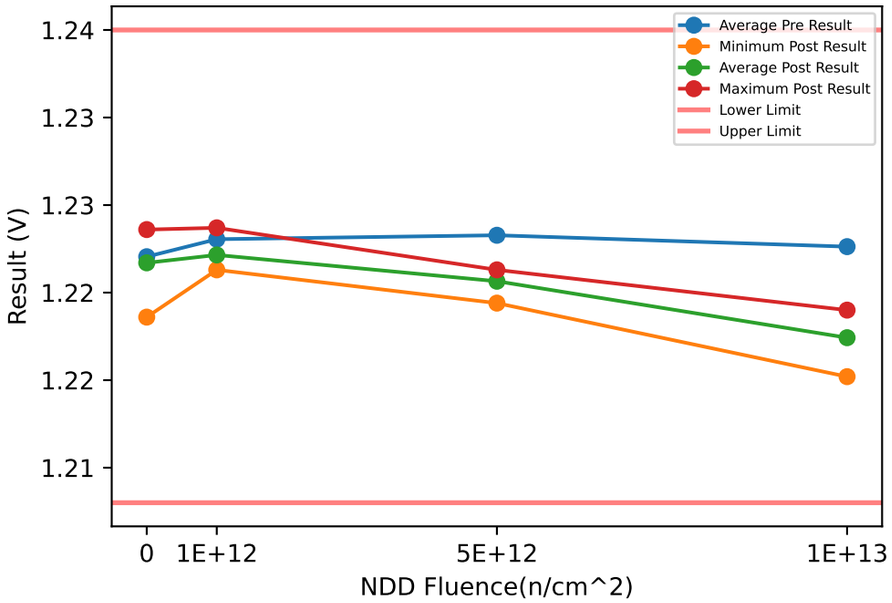
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2187	-0.0006
466	1e+12	NDD	1.2227	1.2214	-0.0013
762	0	CORRELATION	1.2238	1.2232	-0.0006
769	1e+12	NDD	1.2226	1.2221	-0.0005
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2236	1.221	-0.0026
1204	1e+13	NDD	1.2239	1.2191	-0.0048
1284	1e+13	NDD	1.2237	1.2182	-0.0055
1292	5e+12	NDD	1.2233	1.221	-0.0023
1364	1e+13	NDD	1.2227	1.2175	-0.0052
1383	5e+12	NDD	1.2222	1.2194	-0.0028
1388	5e+12	NDD	1.2243	1.2214	-0.0029
1427	1e+13	NDD	1.2204	1.2153	-0.0051
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

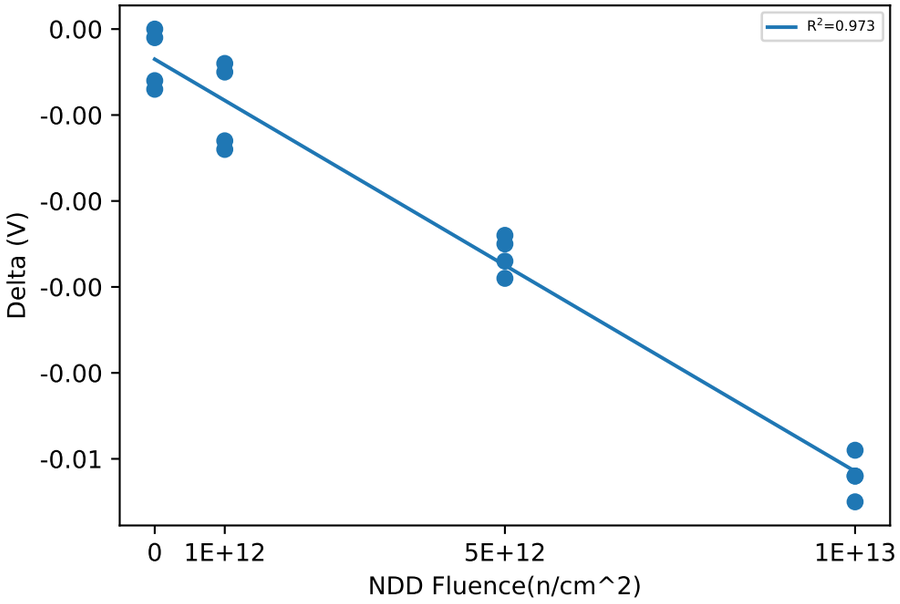
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2238	0.0021245	1.2187	1.2218	1.2236	0.0022279	-0.0006	-0.00035	-0.0001	0.00028868
1e+12	1.2226	1.2231	1.2242	0.00073655	1.2214	1.2222	1.2237	0.0010243	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2222	1.2233	1.2243	0.00087369	1.2194	1.2207	1.2214	0.00088694	-0.0029	-0.00265	-0.0023	0.00026458
1e+13	1.2204	1.2227	1.2239	0.0016049	1.2153	1.2175	1.2191	0.0016215	-0.0055	-0.00515	-0.0048	0.00028868

Device Test: 21.17 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

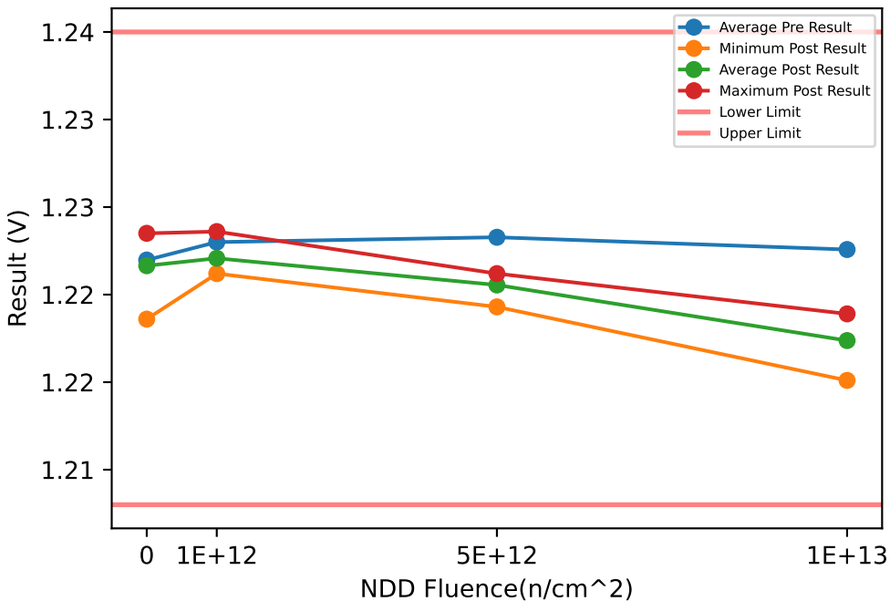
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.223	1.2216	-0.0014
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2237	-0.0004
967	5e+12	NDD	1.2235	1.221	-0.0025
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

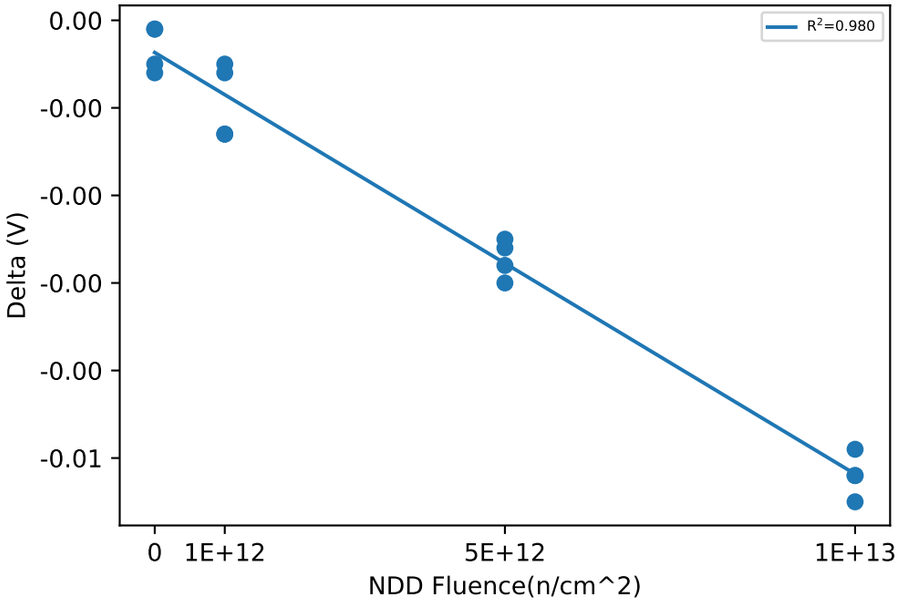
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0021063	1.2186	1.2217	1.2236	0.0022524	-0.0007	-0.00035	0	0.00035119
1e+12	1.2225	1.223	1.2241	0.00073258	1.2213	1.2222	1.2237	0.0010724	-0.0014	-0.0009	-0.0004	0.00052281
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2194	1.2207	1.2213	0.00085049	-0.0029	-0.002625	-0.0024	0.00022174
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2174	1.219	0.0016215	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.19 VOLTAGE|VREF/VREF/5/5/0/0/5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

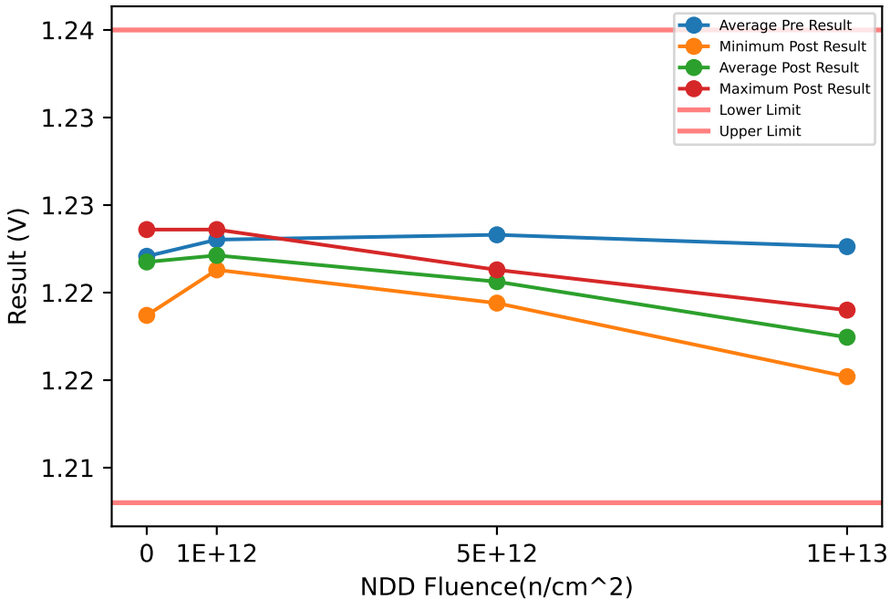
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2192	1.2186	-0.0006
466	1e+12	NDD	1.2225	1.2212	-0.0013
762	0	CORRELATION	1.2236	1.2231	-0.0005
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2238	1.2189	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2208	-0.0025
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2212	-0.003
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

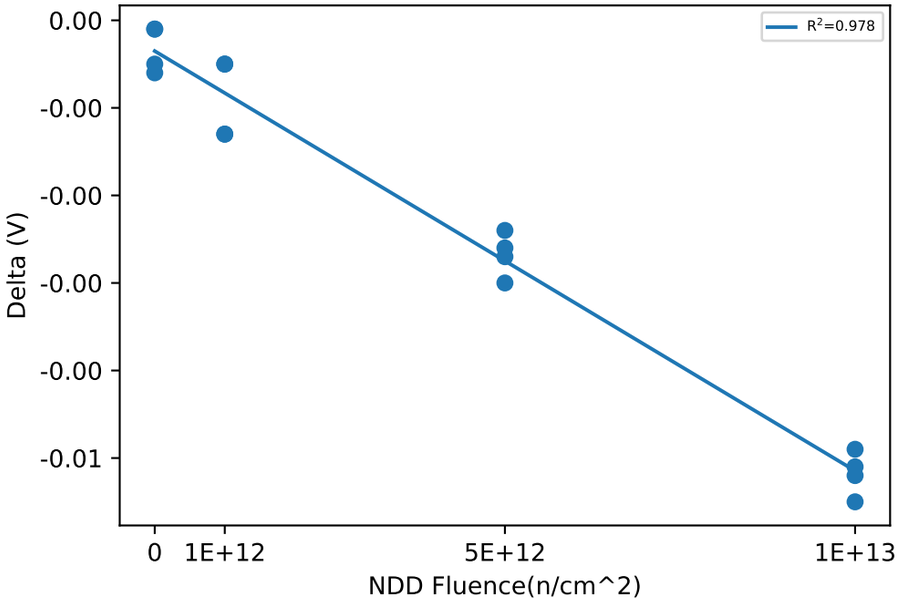
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2192	1.222	1.2236	0.0020982	1.2186	1.2216	1.2235	0.0022279	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2225	1.223	1.2241	0.00075719	1.2212	1.2221	1.2236	0.0010563	-0.0013	-0.000925	-0.0005	0.00043493
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2193	1.2206	1.2212	0.00085049	-0.003	-0.002725	-0.0025	0.00022174
1e+13	1.2203	1.2226	1.2238	0.0016049	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.21 VOLTAGE|VREF/VREF/12/12/0/0/5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

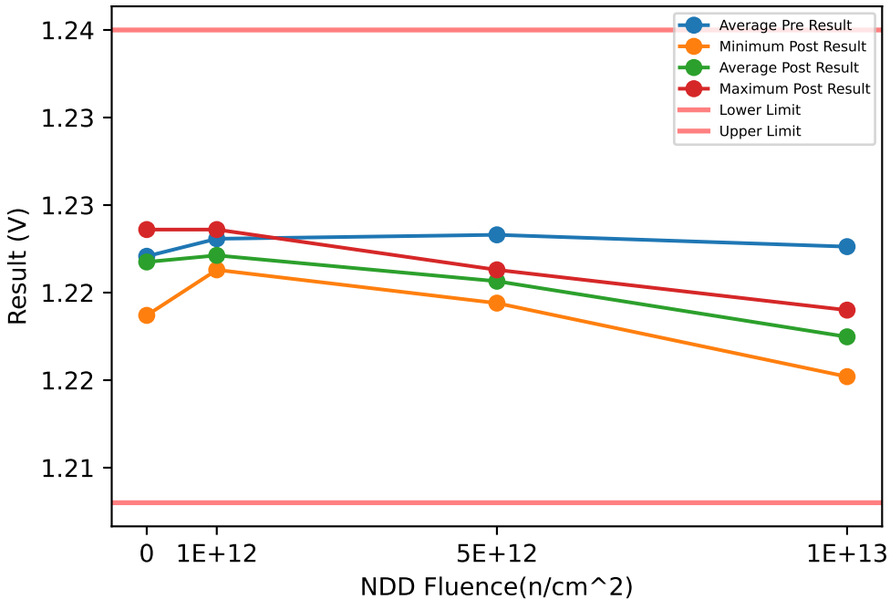
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2187	-0.0006
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2232	-0.0005
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2175	-0.0051
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2243	1.2213	-0.003
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

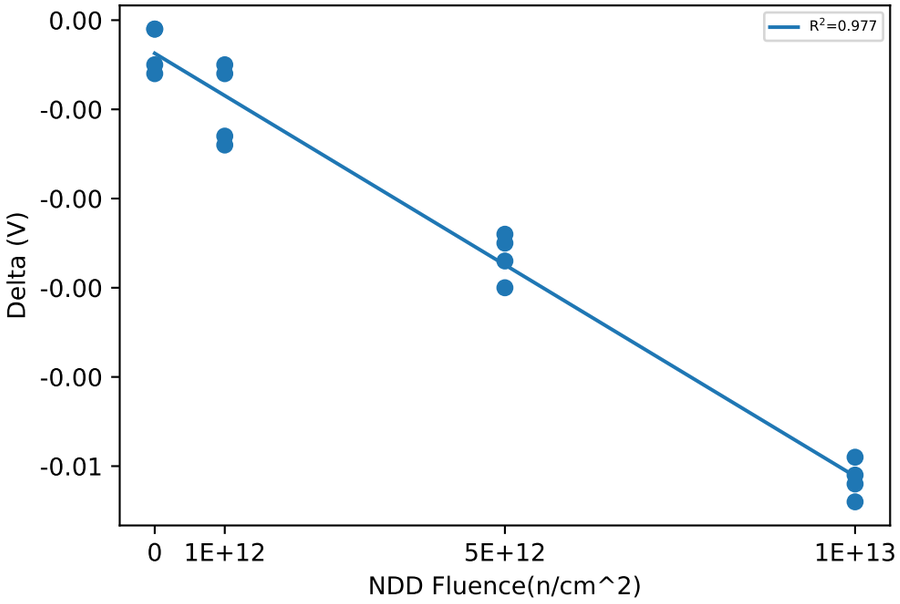
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0020982	1.2187	1.2218	1.2236	0.0022279	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2225	1.223	1.2241	0.00073655	1.2213	1.2221	1.2236	0.0010243	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2221	1.2233	1.2243	0.00090921	1.2194	1.2206	1.2213	0.00083815	-0.003	-0.002675	-0.0024	0.00025
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2174	1.219	0.0016217	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.23 VOLTAGE|VREF/VREF/14/14/0/0/5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

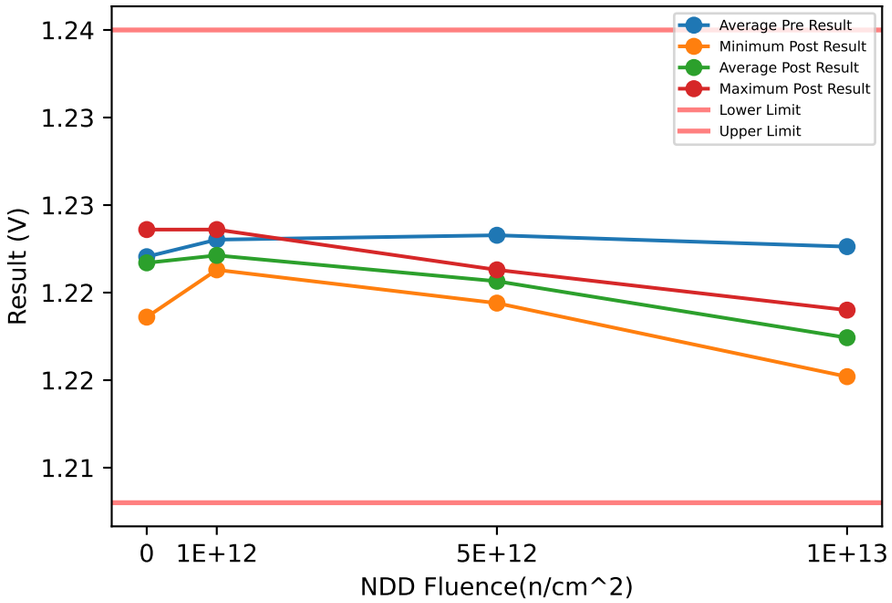
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2187	-0.0006
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2232	-0.0005
769	1e+12	NDD	1.2226	1.222	-0.0006
887	1e+12	NDD	1.223	1.2216	-0.0014
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.221	-0.0025
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2182	-0.0054
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2175	-0.0051
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2243	1.2213	-0.003
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

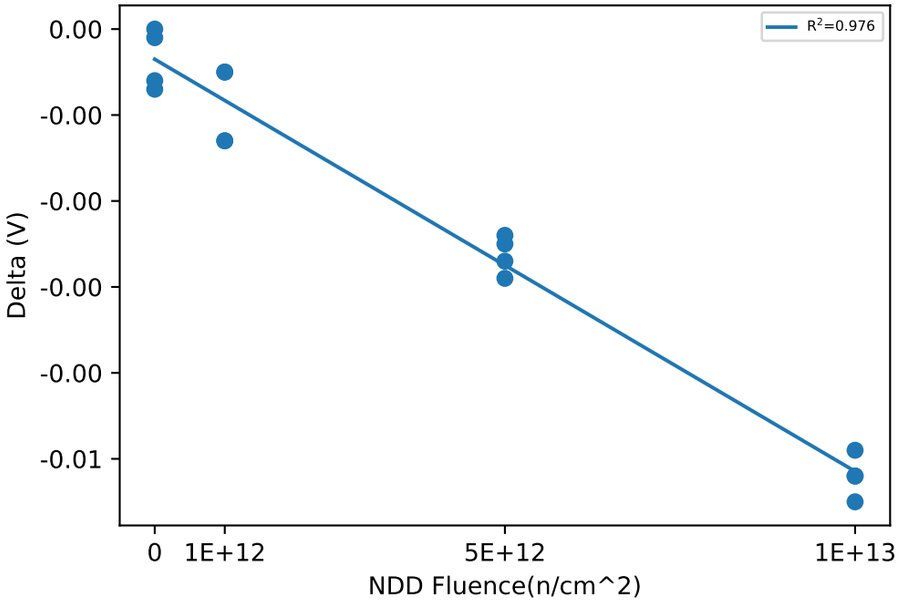
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0020982	1.2187	1.2218	1.2236	0.0022279	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2226	1.2231	1.2241	0.00070887	1.2213	1.2221	1.2236	0.0010243	-0.0014	-0.00095	-0.0005	0.00046547
5e+12	1.2221	1.2233	1.2243	0.00090921	1.2194	1.2207	1.2213	0.00085049	-0.003	-0.00265	-0.0024	0.00026458
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2175	1.219	0.0016358	-0.0054	-0.00515	-0.0049	0.00020817

Device Test: 21.25 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

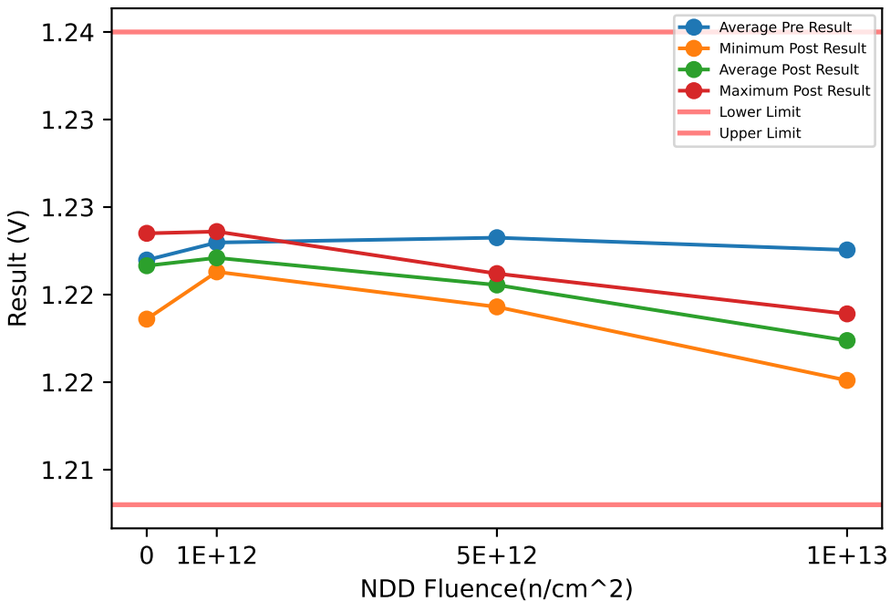
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.221	-0.0025
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

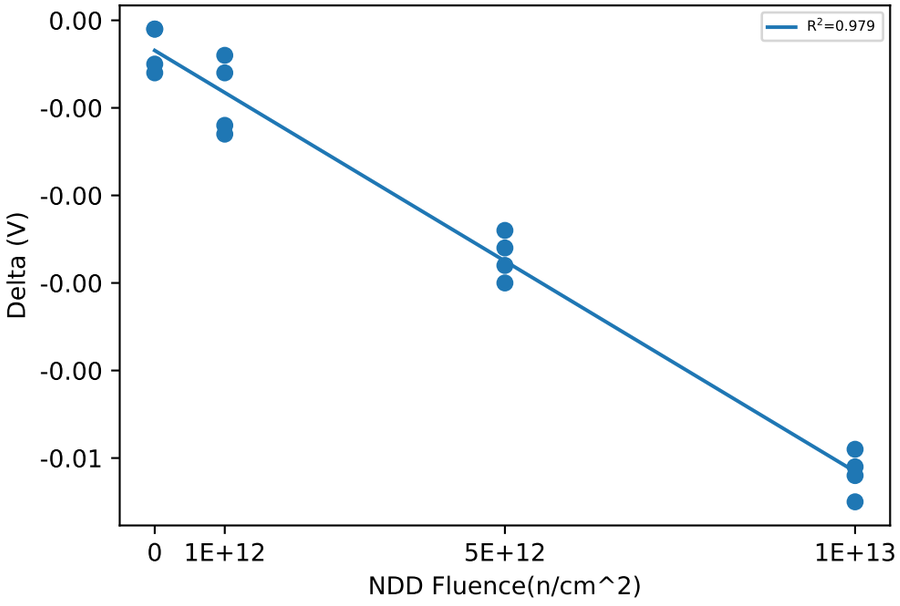
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0021063	1.2186	1.2217	1.2236	0.0022524	-0.0007	-0.00035	0	0.00035119
1e+12	1.2225	1.223	1.2241	0.00073655	1.2213	1.2221	1.2236	0.0010243	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2194	1.2207	1.2213	0.00085049	-0.0029	-0.002625	-0.0024	0.00022174
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2174	1.219	0.0016215	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.27 VOLTAGE|VREF/VREF/5/5/0/1000/5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

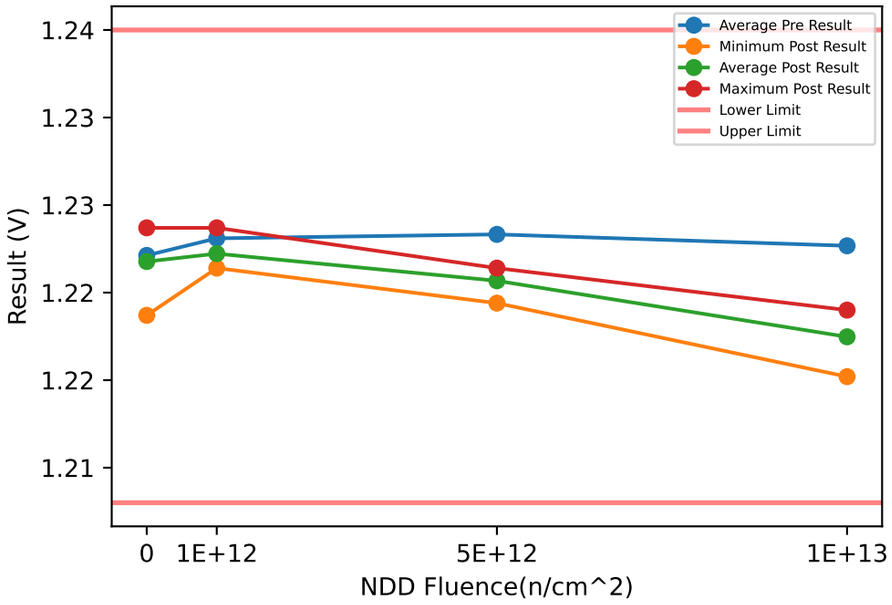
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2192	1.2186	-0.0006
466	1e+12	NDD	1.2225	1.2213	-0.0012
762	0	CORRELATION	1.2236	1.2231	-0.0005
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.224	1.2236	-0.0004
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2238	1.2189	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2232	1.2208	-0.0024
1364	1e+13	NDD	1.2225	1.2174	-0.0051
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2212	-0.003
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

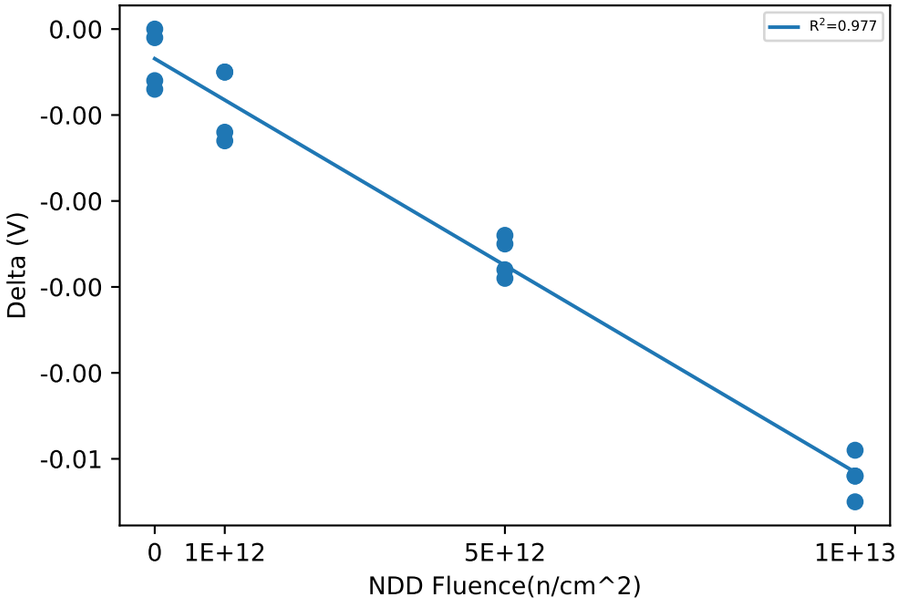
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2192	1.222	1.2236	0.0020982	1.2186	1.2216	1.2235	0.0022279	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2225	1.223	1.224	0.00070887	1.2213	1.2221	1.2236	0.0010296	-0.0013	-0.000875	-0.0004	0.00044253
5e+12	1.2221	1.2232	1.2242	0.00087369	1.2193	1.2206	1.2212	0.00085049	-0.003	-0.0027	-0.0024	0.0002582
1e+13	1.2203	1.2226	1.2238	0.0016052	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.29 VOLTAGE|VREF/VREF/12/12/0/1000/5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

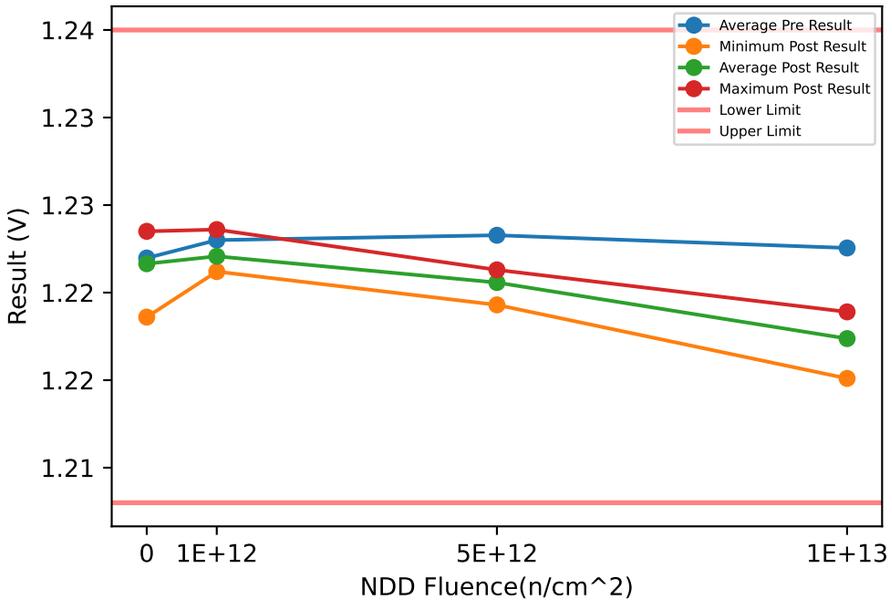
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2194	1.2187	-0.0007
466	1e+12	NDD	1.2226	1.2214	-0.0012
762	0	CORRELATION	1.2238	1.2232	-0.0006
769	1e+12	NDD	1.2226	1.2221	-0.0005
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2235	1.221	-0.0025
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2237	1.2182	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2227	1.2175	-0.0052
1383	5e+12	NDD	1.2222	1.2194	-0.0028
1388	5e+12	NDD	1.2243	1.2214	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2237	0

Test Statistics (V)

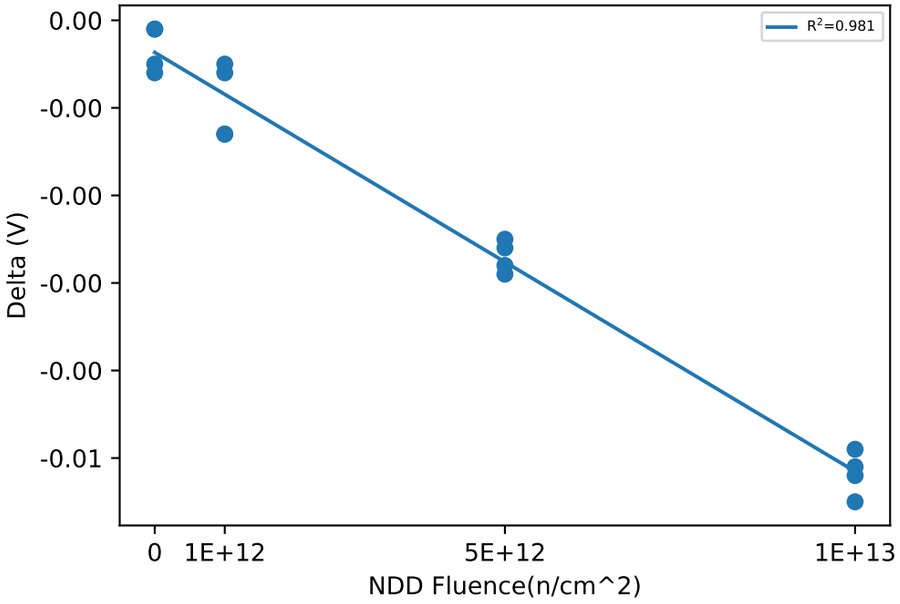
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2194	1.2221	1.2238	0.0020807	1.2187	1.2218	1.2237	0.0022559	-0.0007	-0.00035	0	0.00035119
1e+12	1.2226	1.2231	1.2242	0.00075719	1.2214	1.2222	1.2237	0.0010243	-0.0013	-0.000875	-0.0005	0.00043493
5e+12	1.2222	1.2233	1.2243	0.00086554	1.2194	1.2207	1.2214	0.00087702	-0.0029	-0.00265	-0.0024	0.00023805
1e+13	1.2204	1.2227	1.2239	0.0016049	1.2152	1.2175	1.219	0.0016358	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.3 VOLTAGE|VREF/VREF/5/5/0/0/5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

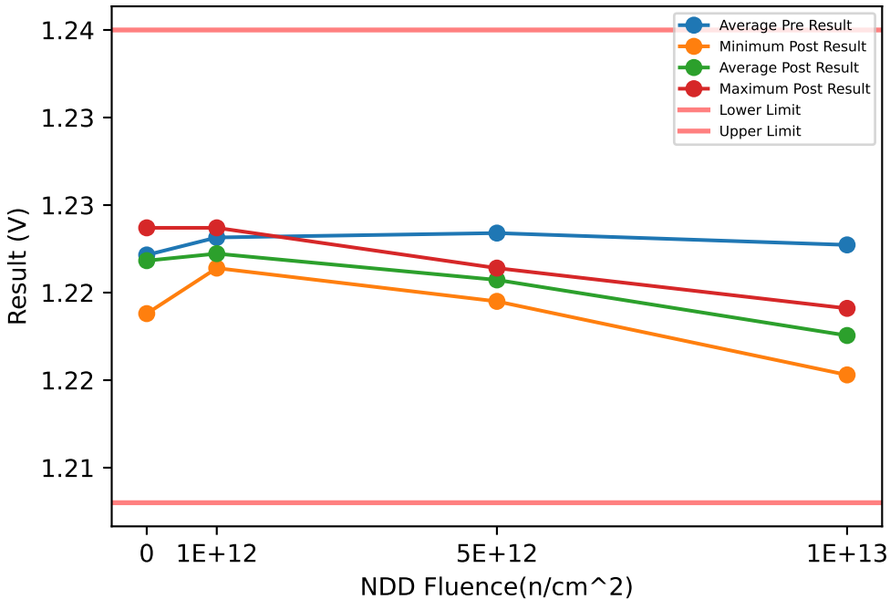
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2192	1.2186	-0.0006
466	1e+12	NDD	1.2225	1.2212	-0.0013
762	0	CORRELATION	1.2236	1.2231	-0.0005
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2238	1.2189	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2208	-0.0025
1364	1e+13	NDD	1.2225	1.2174	-0.0051
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

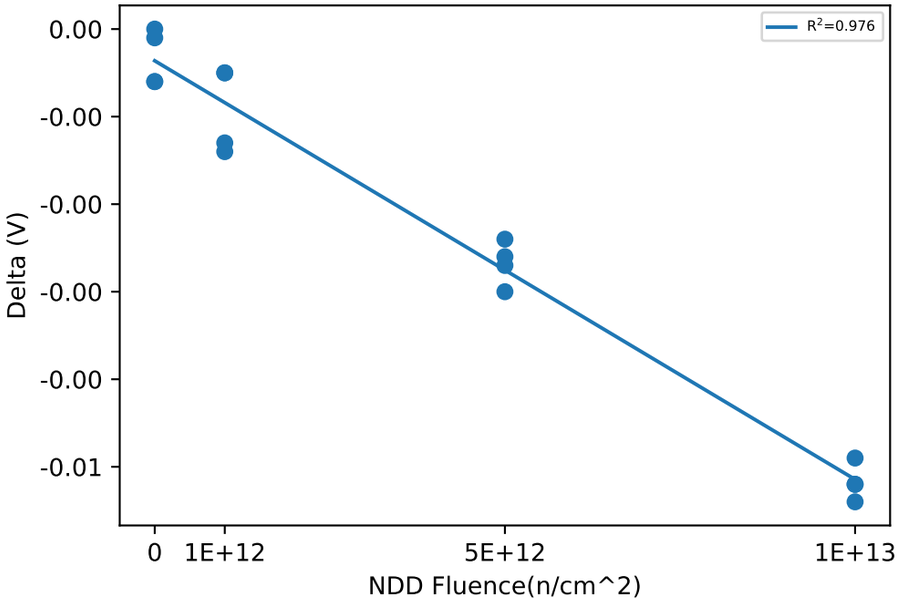
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2192	1.222	1.2236	0.0020982	1.2186	1.2216	1.2235	0.0022279	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2225	1.223	1.2241	0.00075719	1.2212	1.2221	1.2236	0.0010563	-0.0013	-0.000925	-0.0005	0.00043493
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2193	1.2206	1.2213	0.00087702	-0.0029	-0.0027	-0.0025	0.00018257
1e+13	1.2203	1.2226	1.2238	0.0016052	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.31 VOLTAGE|VREF/VREF/14/14/0/1000/5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

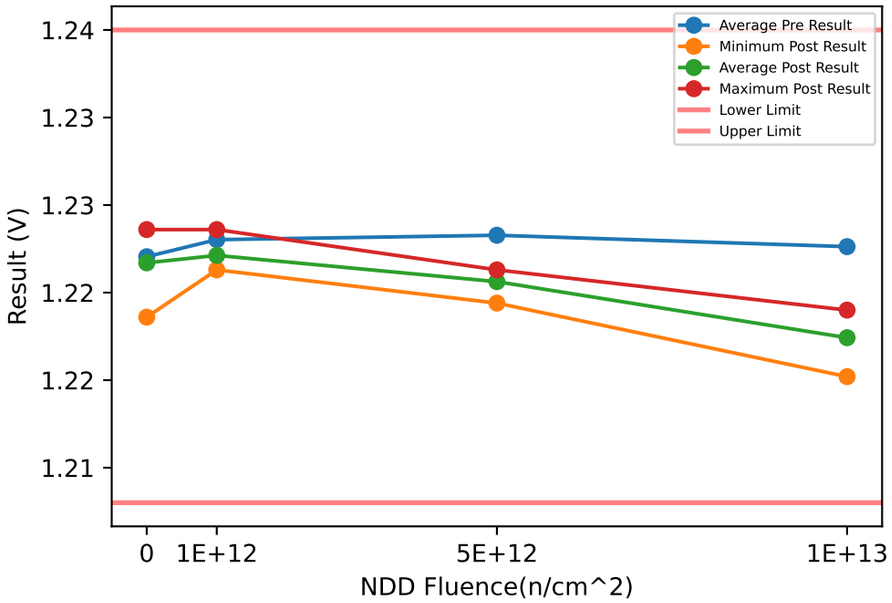
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2194	1.2188	-0.0006
466	1e+12	NDD	1.2227	1.2214	-0.0013
762	0	CORRELATION	1.2238	1.2232	-0.0006
769	1e+12	NDD	1.2226	1.2221	-0.0005
887	1e+12	NDD	1.2231	1.2217	-0.0014
891	0	CORRELATION	1.2216	1.2216	0
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2236	1.221	-0.0026
1204	1e+13	NDD	1.224	1.2191	-0.0049
1284	1e+13	NDD	1.2237	1.2183	-0.0054
1292	5e+12	NDD	1.2234	1.221	-0.0024
1364	1e+13	NDD	1.2227	1.2175	-0.0052
1383	5e+12	NDD	1.2222	1.2195	-0.0027
1388	5e+12	NDD	1.2244	1.2214	-0.003
1427	1e+13	NDD	1.2205	1.2153	-0.0052
1666	0	CORRELATION	1.2238	1.2237	-0.0001

Test Statistics (V)

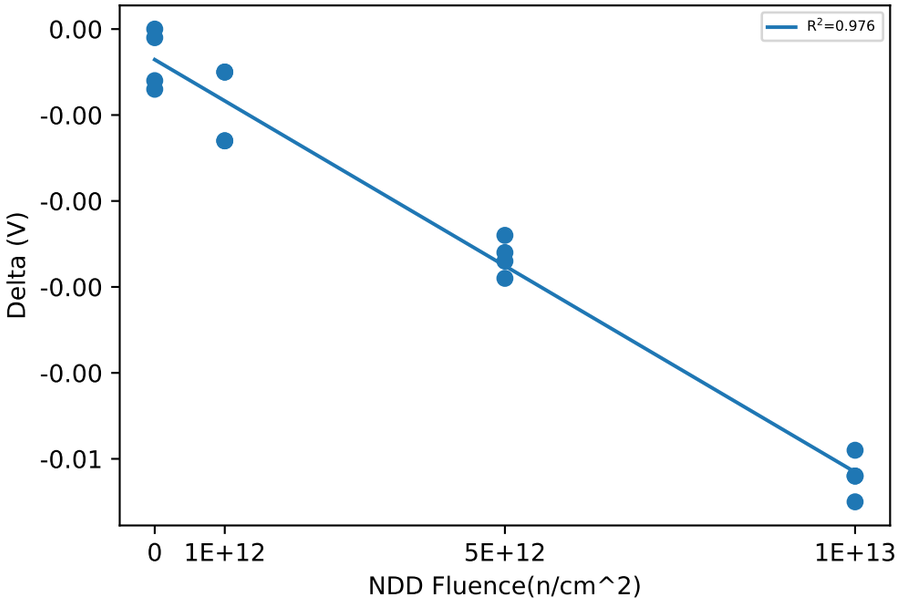
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2194	1.2222	1.2238	0.0021063	1.2188	1.2218	1.2237	0.0022066	-0.0006	-0.000325	0	0.00032016
1e+12	1.2226	1.2231	1.2242	0.00073258	1.2214	1.2222	1.2237	0.0010243	-0.0014	-0.000925	-0.0005	0.00049244
5e+12	1.2222	1.2234	1.2244	0.00090921	1.2195	1.2207	1.2214	0.00083815	-0.003	-0.002675	-0.0024	0.00025
1e+13	1.2205	1.2227	1.224	0.001584	1.2153	1.2176	1.2191	0.0016361	-0.0054	-0.005175	-0.0049	0.00020616

Device Test: 21.33 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

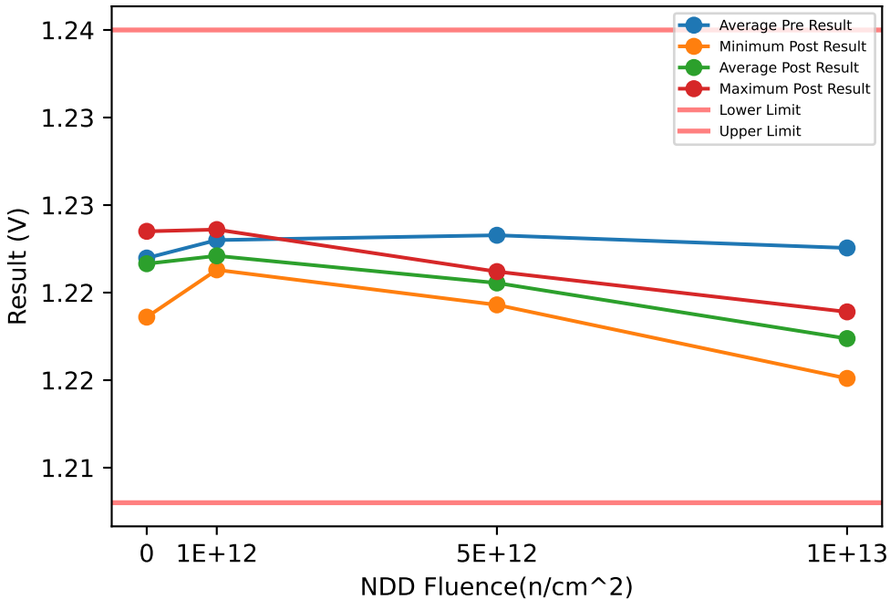
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

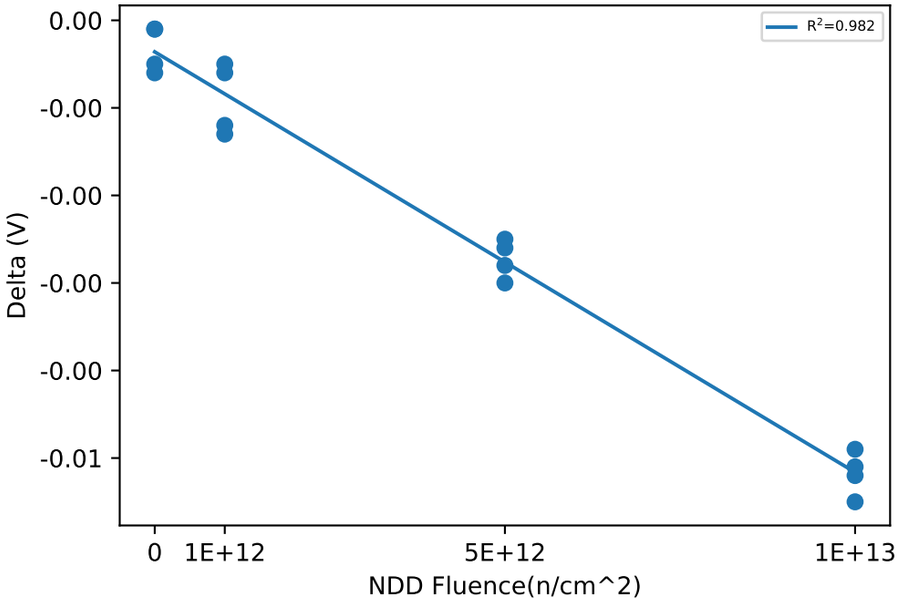
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0021063	1.2186	1.2217	1.2236	0.0022524	-0.0007	-0.00035	0	0.00035119
1e+12	1.2225	1.223	1.2241	0.00073655	1.2213	1.2221	1.2236	0.0010243	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2194	1.2206	1.2213	0.00083815	-0.0029	-0.00265	-0.0024	0.00020817
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2174	1.219	0.0016215	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.35 VOLTAGE|VREF/VREF/5/5/0/1000/5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

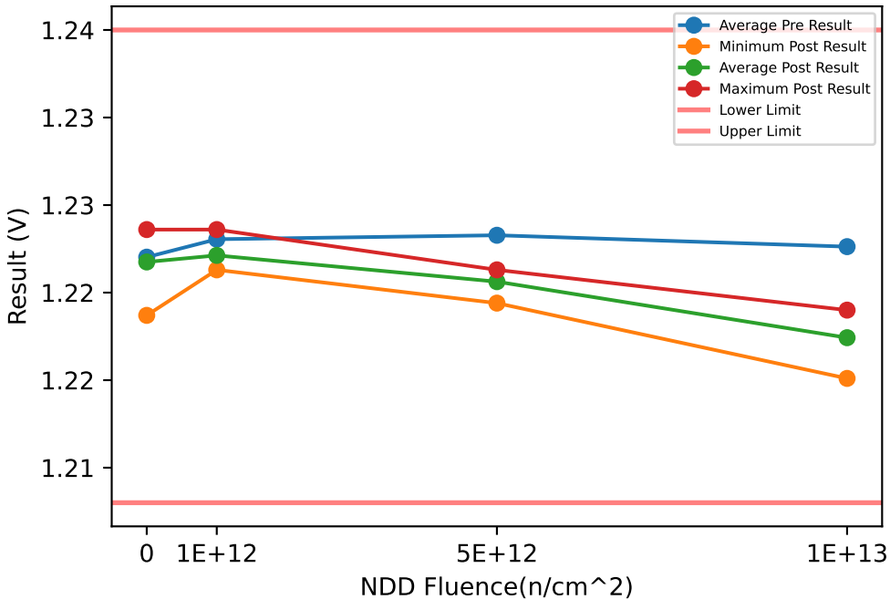
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2192	1.2186	-0.0006
466	1e+12	NDD	1.2225	1.2213	-0.0012
762	0	CORRELATION	1.2236	1.2231	-0.0005
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2238	1.2189	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2208	-0.0025
1364	1e+13	NDD	1.2225	1.2174	-0.0051
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2212	-0.003
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

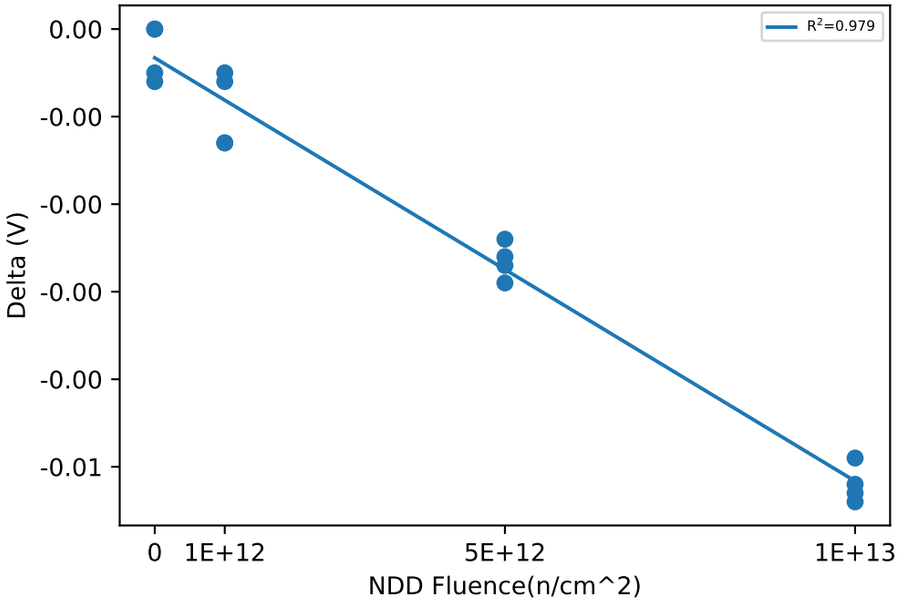
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2192	1.222	1.2236	0.0020982	1.2186	1.2216	1.2235	0.0022279	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2225	1.223	1.2241	0.00075719	1.2213	1.2221	1.2236	0.0010296	-0.0013	-0.0009	-0.0005	0.00040825
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2193	1.2206	1.2212	0.00085049	-0.003	-0.002725	-0.0025	0.00022174
1e+13	1.2203	1.2226	1.2238	0.0016052	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.37 VOLTAGE|VREF/VREF/12/12/0/1000/5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

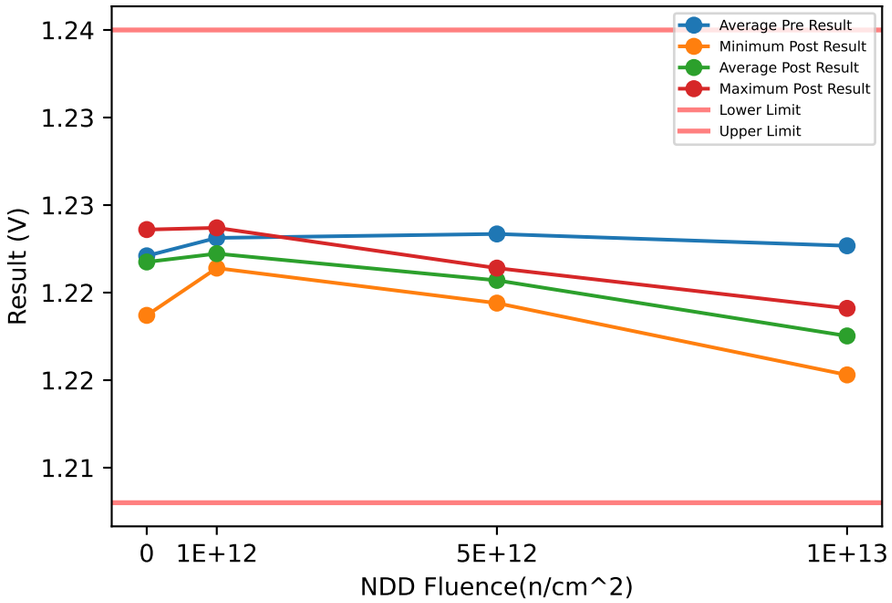
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2187	-0.0006
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2232	-0.0005
769	1e+12	NDD	1.2226	1.222	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2182	-0.0054
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2151	-0.0053
1666	0	CORRELATION	1.2236	1.2236	0

Test Statistics (V)

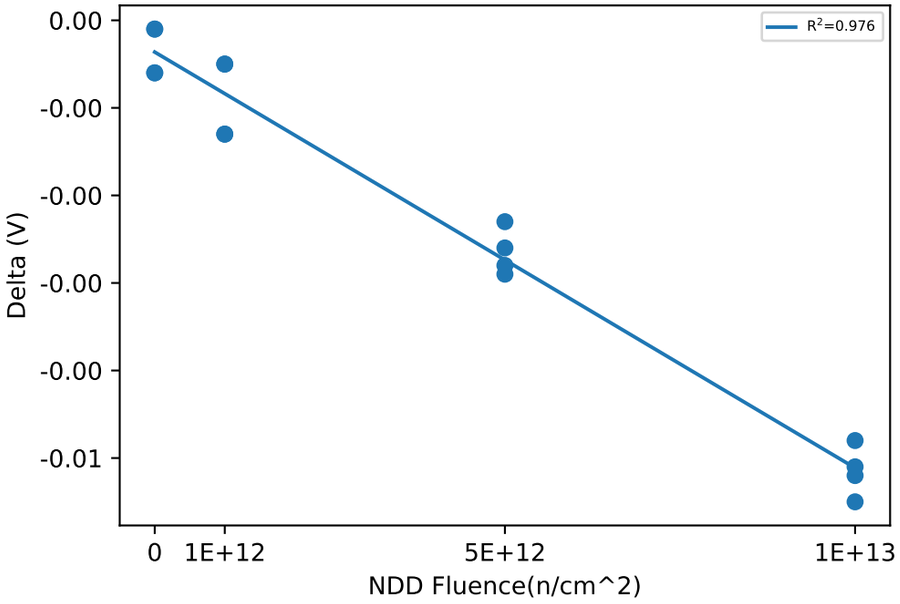
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.222	1.2237	0.0020807	1.2187	1.2218	1.2236	0.0022279	-0.0006	-0.000275	0	0.00032016
1e+12	1.2226	1.223	1.2241	0.00071414	1.2213	1.2221	1.2236	0.0010243	-0.0013	-0.000925	-0.0005	0.00043493
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2194	1.2206	1.2213	0.00083815	-0.0029	-0.00265	-0.0024	0.00020817
1e+13	1.2204	1.2226	1.2239	0.001584	1.2151	1.2174	1.219	0.001682	-0.0054	-0.0052	-0.0049	0.00021602

Device Test: 21.39 VOLTAGE|VREF/VREF/14/14/0/1000/5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

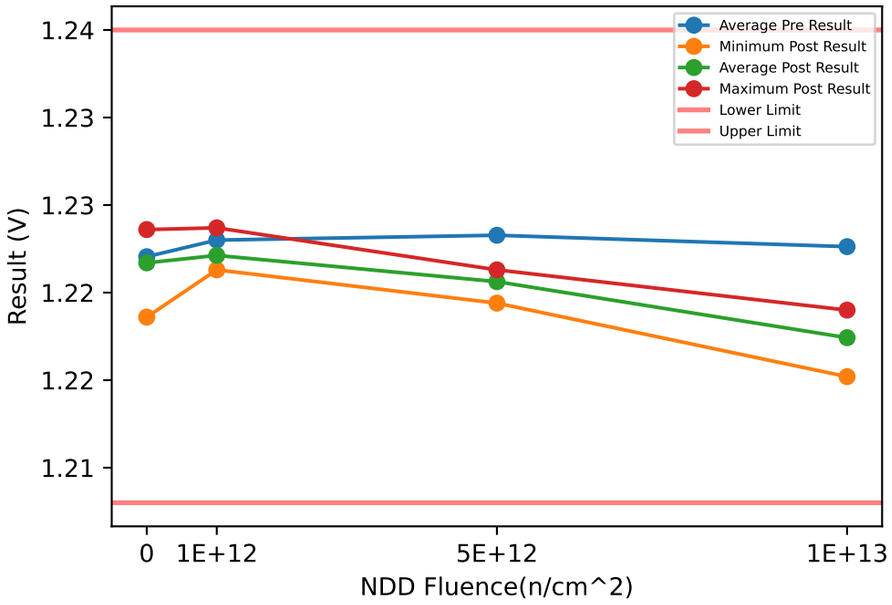
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2187	-0.0006
466	1e+12	NDD	1.2227	1.2214	-0.0013
762	0	CORRELATION	1.2238	1.2232	-0.0006
769	1e+12	NDD	1.2226	1.2221	-0.0005
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2236	1.221	-0.0026
1204	1e+13	NDD	1.2239	1.2191	-0.0048
1284	1e+13	NDD	1.2237	1.2182	-0.0055
1292	5e+12	NDD	1.2233	1.221	-0.0023
1364	1e+13	NDD	1.2227	1.2175	-0.0052
1383	5e+12	NDD	1.2222	1.2194	-0.0028
1388	5e+12	NDD	1.2243	1.2214	-0.0029
1427	1e+13	NDD	1.2204	1.2153	-0.0051
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

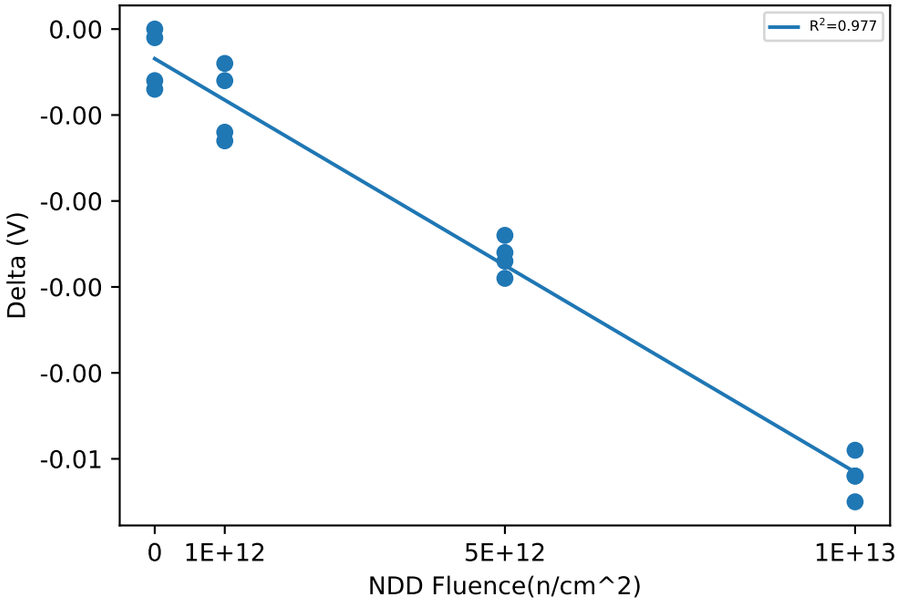
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2238	0.0021245	1.2187	1.2218	1.2236	0.0022279	-0.0006	-0.00035	-0.0001	0.00028868
1e+12	1.2226	1.2231	1.2242	0.00073655	1.2214	1.2222	1.2237	0.0010243	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2222	1.2233	1.2243	0.00087369	1.2194	1.2207	1.2214	0.00088694	-0.0029	-0.00265	-0.0023	0.00026458
1e+13	1.2204	1.2227	1.2239	0.0016049	1.2153	1.2175	1.2191	0.0016215	-0.0055	-0.00515	-0.0048	0.00028868

Device Test: 21.41 VOLTAGE|VREF/VREF/4.5/4.5/0/1000/4.5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

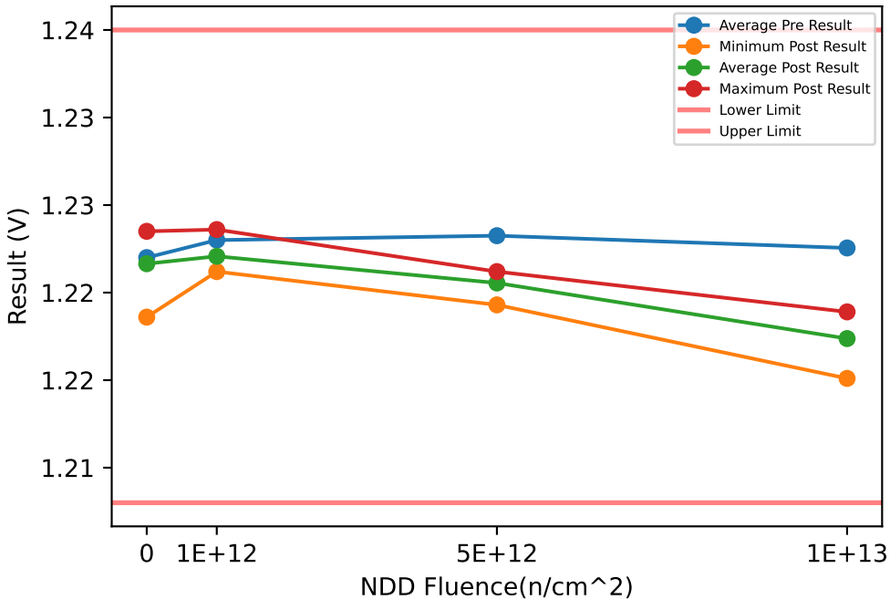
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2225	1.2213	-0.0012
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2237	-0.0004
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

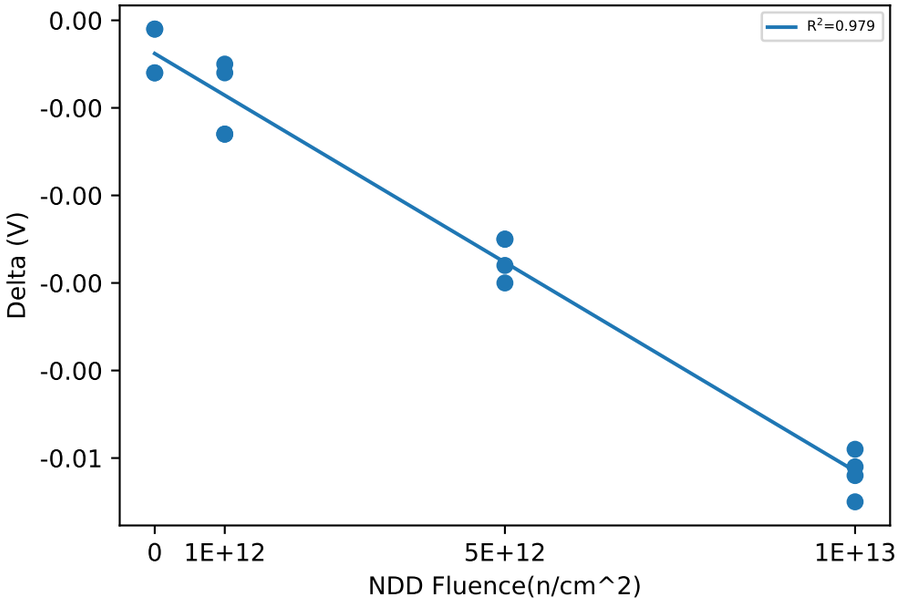
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0021063	1.2186	1.2217	1.2236	0.0022524	-0.0007	-0.00035	0	0.00035119
1e+12	1.2225	1.223	1.2241	0.00075719	1.2213	1.2221	1.2237	0.0010782	-0.0013	-0.000875	-0.0004	0.00044253
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2194	1.2206	1.2213	0.00083815	-0.0029	-0.00265	-0.0024	0.00020817
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2174	1.219	0.0016215	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.43 VOLTAGE|VREF/VREF/5/5/0/1000/5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

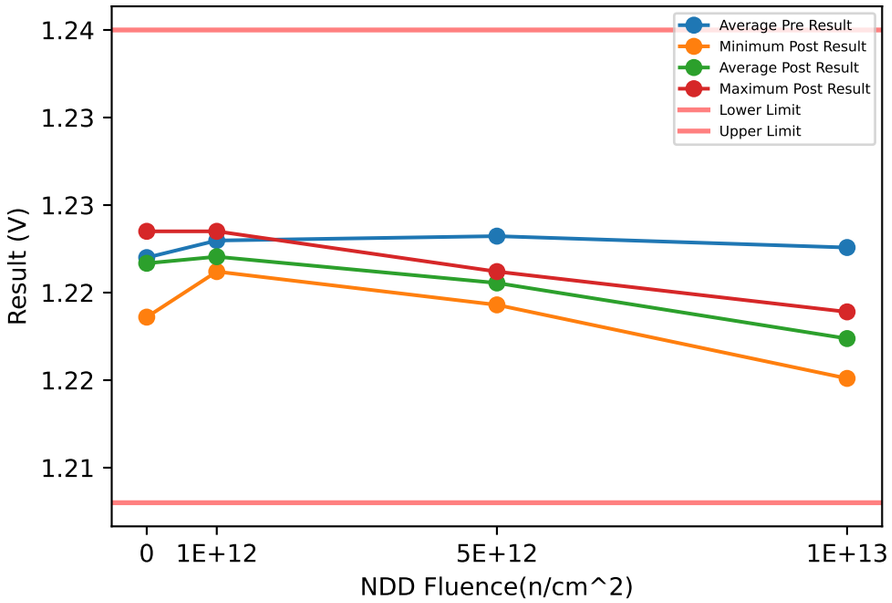
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2192	1.2186	-0.0006
466	1e+12	NDD	1.2225	1.2212	-0.0013
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2229	1.2216	-0.0013
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2234	1.2209	-0.0025
1204	1e+13	NDD	1.2238	1.2189	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2208	-0.0025
1364	1e+13	NDD	1.2225	1.2174	-0.0051
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2212	-0.003
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

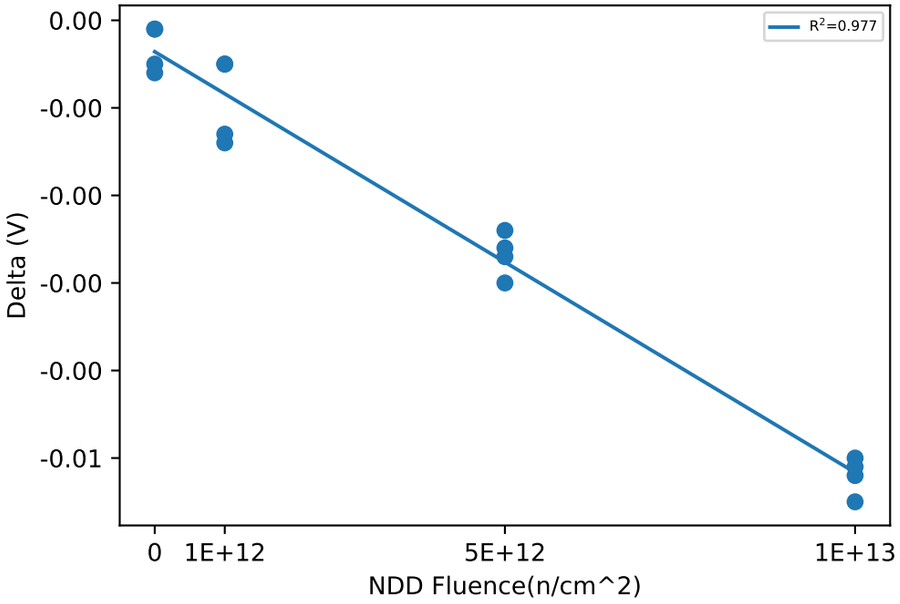
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2192	1.222	1.2237	0.0021245	1.2186	1.2216	1.2235	0.0022279	-0.0006	-0.00035	-0.0001	0.00028868
1e+12	1.2225	1.223	1.2241	0.00075719	1.2212	1.2221	1.2236	0.0010563	-0.0013	-0.000925	-0.0005	0.00043493
5e+12	1.2221	1.2232	1.2242	0.00086603	1.2193	1.2206	1.2212	0.00085049	-0.003	-0.0027	-0.0025	0.00024495
1e+13	1.2203	1.2226	1.2238	0.0016052	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.45 VOLTAGE|VREF/VREF/12/12/0/1000/5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

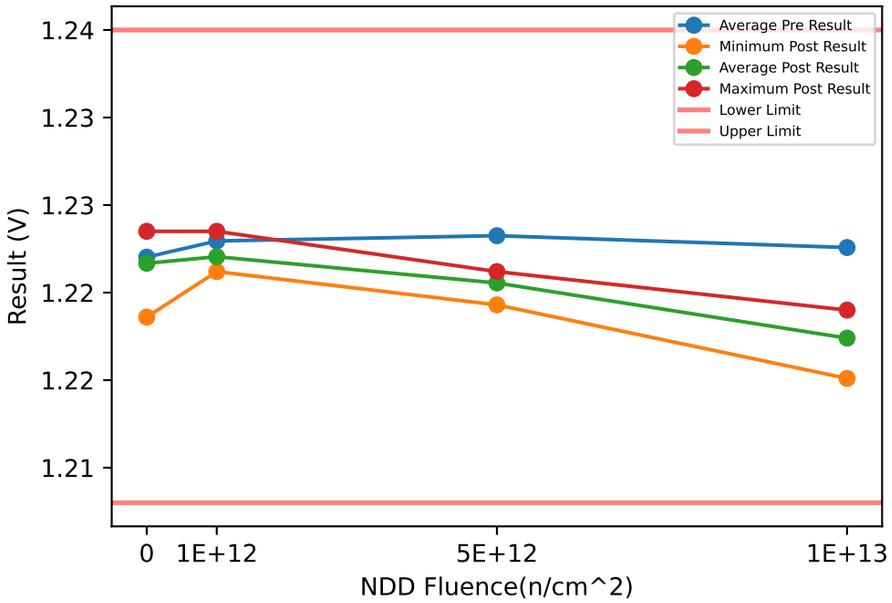
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2192	1.2186	-0.0006
466	1e+12	NDD	1.2225	1.2212	-0.0013
762	0	CORRELATION	1.2237	1.2232	-0.0005
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.2229	1.2215	-0.0014
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.224	1.2235	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2239	1.2189	-0.005
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2232	1.2208	-0.0024
1364	1e+13	NDD	1.2225	1.2174	-0.0051
1383	5e+12	NDD	1.222	1.2193	-0.0027
1388	5e+12	NDD	1.2242	1.2212	-0.003
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

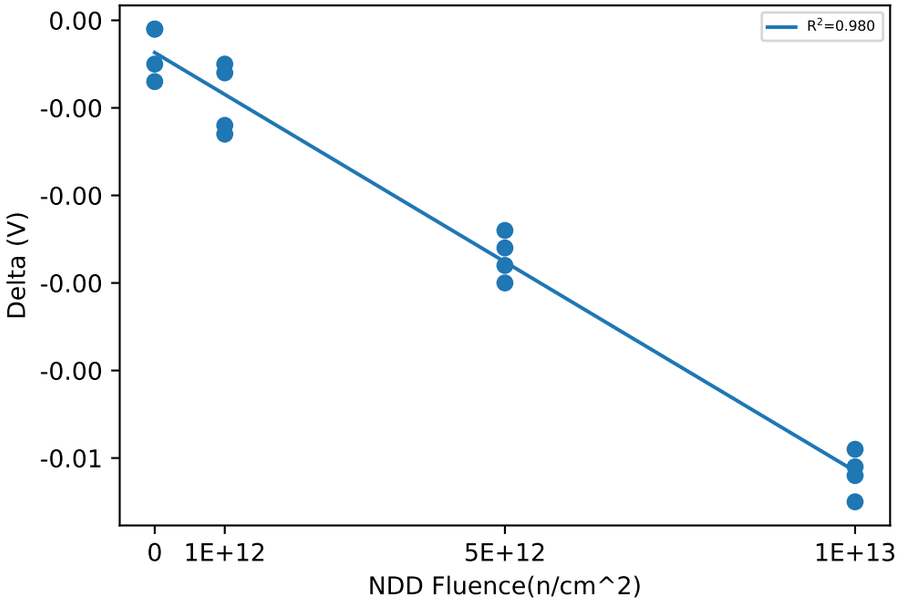
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2192	1.222	1.2237	0.0021245	1.2186	1.2217	1.2235	0.00225	-0.0006	-0.000325	-0.0001	0.000263
1e+12	1.2225	1.223	1.224	0.00070887	1.2212	1.2221	1.2235	0.0010214	-0.0014	-0.000925	-0.0005	0.00049244
5e+12	1.222	1.2232	1.2242	0.00091788	1.2193	1.2206	1.2212	0.00085049	-0.003	-0.002675	-0.0024	0.00025
1e+13	1.2203	1.2226	1.2239	0.0016317	1.2151	1.2174	1.2189	0.0016358	-0.0055	-0.0052	-0.005	0.00021602

Device Test: 21.47 VOLTAGE|VREF/VREF/14/14/0/1000/5/1MHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

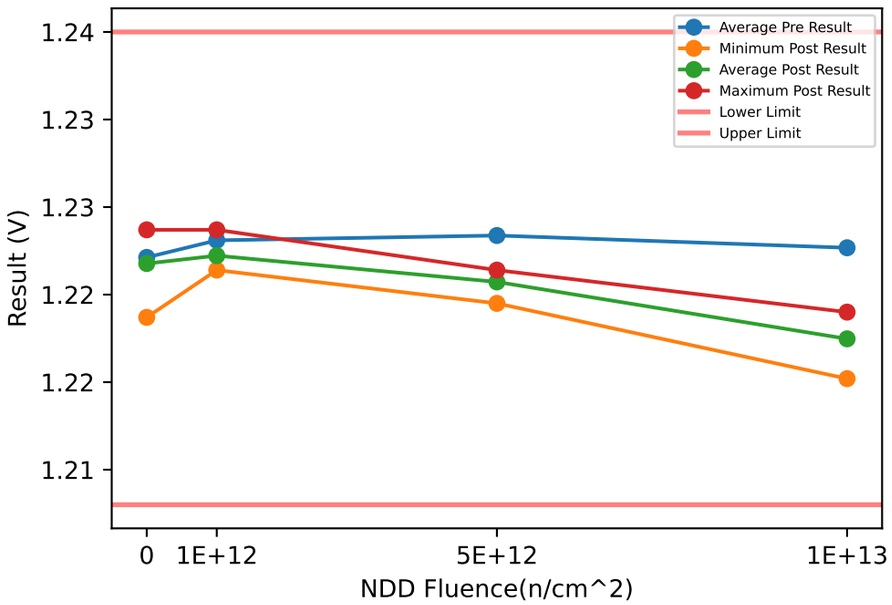
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2225	1.2212	-0.0013
762	0	CORRELATION	1.2237	1.2232	-0.0005
769	1e+12	NDD	1.2225	1.2219	-0.0006
887	1e+12	NDD	1.2228	1.2216	-0.0012
891	0	CORRELATION	1.2215	1.2214	-0.0001
927	1e+12	NDD	1.224	1.2235	-0.0005
967	5e+12	NDD	1.2235	1.2209	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2232	1.2208	-0.0024
1364	1e+13	NDD	1.2225	1.2174	-0.0051
1383	5e+12	NDD	1.2221	1.2193	-0.0028
1388	5e+12	NDD	1.2242	1.2212	-0.003
1427	1e+13	NDD	1.2203	1.2151	-0.0052
1666	0	CORRELATION	1.2236	1.2235	-0.0001

Test Statistics (V)

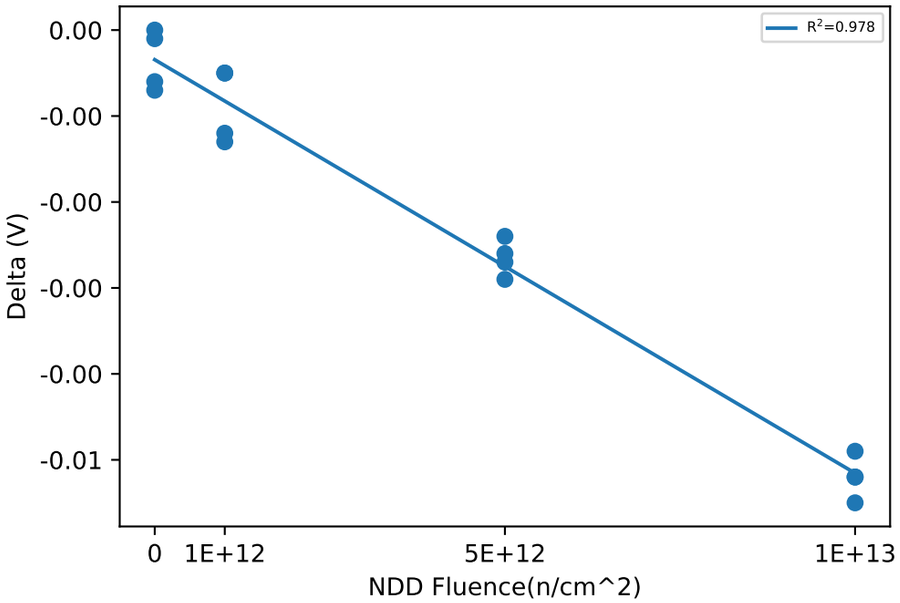
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.222	1.2237	0.0020807	1.2186	1.2217	1.2235	0.00225	-0.0007	-0.00035	-0.0001	0.0003
1e+12	1.2225	1.2229	1.224	0.00071414	1.2212	1.2221	1.2235	0.0010083	-0.0013	-0.0009	-0.0005	0.00040825
5e+12	1.2221	1.2232	1.2242	0.00087369	1.2193	1.2206	1.2212	0.00085049	-0.003	-0.0027	-0.0024	0.0002582
1e+13	1.2203	1.2226	1.2239	0.0016317	1.2151	1.2174	1.219	0.0016673	-0.0055	-0.005175	-0.0049	0.00025

Device Test: 21.5 VOLTAGE|VREF/VREF/12/12/0/0/5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

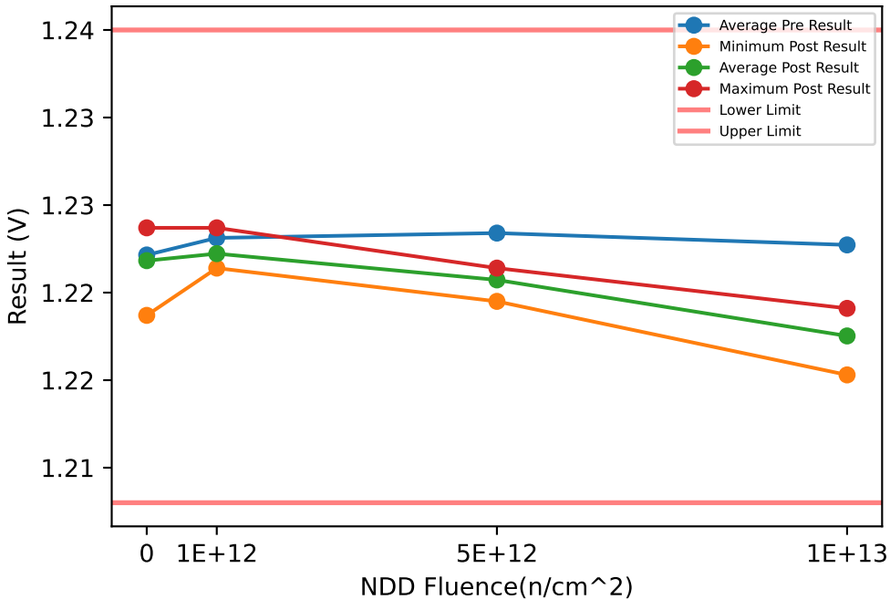
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2194	1.2187	-0.0007
466	1e+12	NDD	1.2226	1.2214	-0.0012
762	0	CORRELATION	1.2238	1.2232	-0.0006
769	1e+12	NDD	1.2226	1.2221	-0.0005
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2216	1.2215	-0.0001
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2236	1.221	-0.0026
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2237	1.2182	-0.0055
1292	5e+12	NDD	1.2234	1.221	-0.0024
1364	1e+13	NDD	1.2227	1.2175	-0.0052
1383	5e+12	NDD	1.2222	1.2195	-0.0027
1388	5e+12	NDD	1.2243	1.2214	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2237	0

Test Statistics (V)

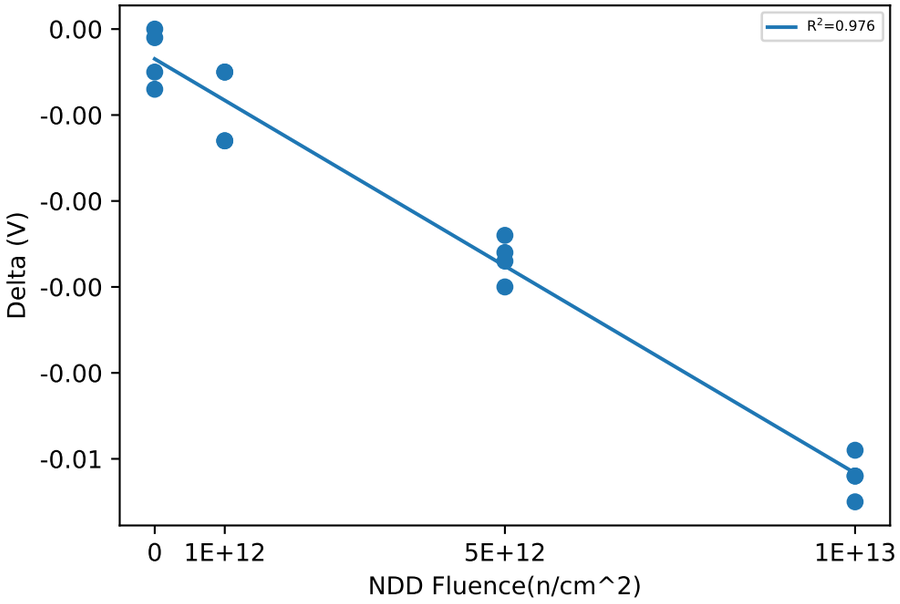
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2194	1.2221	1.2238	0.0020807	1.2187	1.2218	1.2237	0.0022559	-0.0007	-0.00035	0	0.00035119
1e+12	1.2226	1.2231	1.2242	0.00075719	1.2214	1.2222	1.2237	0.0010243	-0.0013	-0.000875	-0.0005	0.00043493
5e+12	1.2222	1.2234	1.2243	0.00087321	1.2195	1.2207	1.2214	0.00083815	-0.0029	-0.00265	-0.0024	0.00020817
1e+13	1.2204	1.2227	1.2239	0.0016049	1.2152	1.2175	1.219	0.0016358	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.7 VOLTAGE|VREF/VREF/14/14/0/0/5/100kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

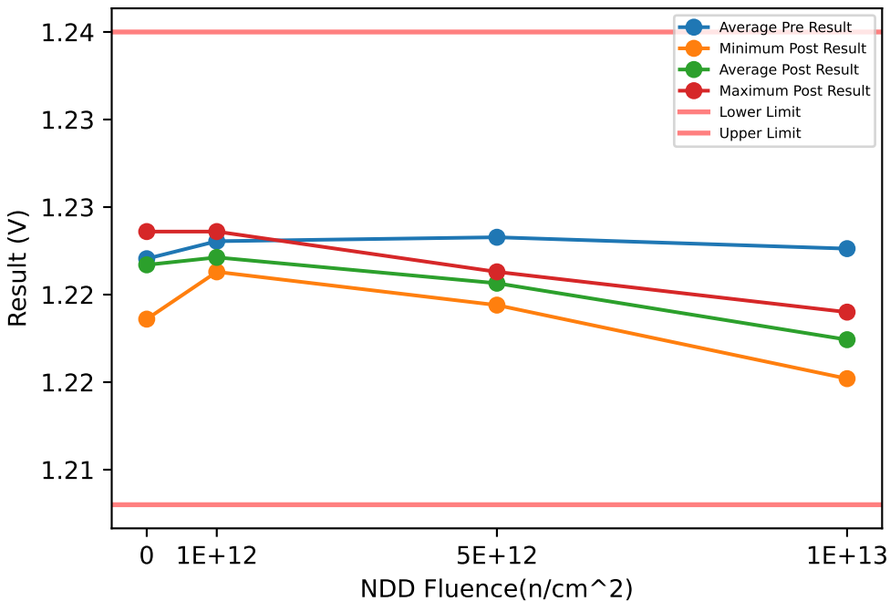
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2194	1.2187	-0.0007
466	1e+12	NDD	1.2227	1.2214	-0.0013
762	0	CORRELATION	1.2238	1.2233	-0.0005
769	1e+12	NDD	1.2226	1.2221	-0.0005
887	1e+12	NDD	1.223	1.2217	-0.0013
891	0	CORRELATION	1.2216	1.2216	0
927	1e+12	NDD	1.2242	1.2237	-0.0005
967	5e+12	NDD	1.2236	1.221	-0.0026
1204	1e+13	NDD	1.224	1.2191	-0.0049
1284	1e+13	NDD	1.2237	1.2182	-0.0055
1292	5e+12	NDD	1.2234	1.221	-0.0024
1364	1e+13	NDD	1.2227	1.2175	-0.0052
1383	5e+12	NDD	1.2222	1.2195	-0.0027
1388	5e+12	NDD	1.2244	1.2214	-0.003
1427	1e+13	NDD	1.2205	1.2153	-0.0052
1666	0	CORRELATION	1.2238	1.2237	-0.0001

Test Statistics (V)

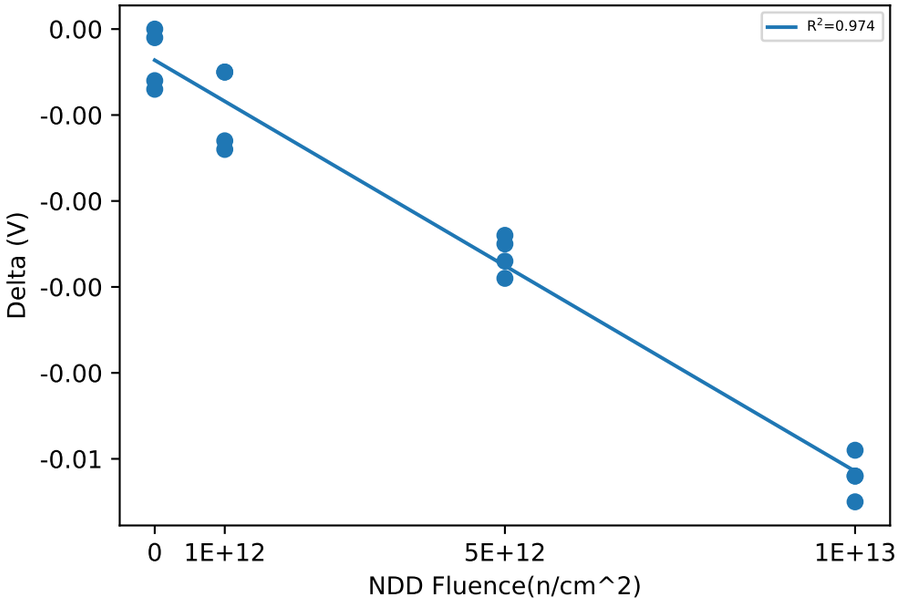
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2194	1.2222	1.2238	0.0021063	1.2187	1.2218	1.2237	0.0022736	-0.0007	-0.000325	0	0.0003304
1e+12	1.2226	1.2231	1.2242	0.00073655	1.2214	1.2222	1.2237	0.0010243	-0.0013	-0.0009	-0.0005	0.00046188
5e+12	1.2222	1.2234	1.2244	0.00090921	1.2195	1.2207	1.2214	0.00083815	-0.003	-0.002675	-0.0024	0.00025
1e+13	1.2205	1.2227	1.224	0.001584	1.2153	1.2175	1.2191	0.0016215	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 21.9 VOLTAGE|VREF/VREF/4.5/4.5/0/0/4.5/500kHz//@V_REFCAP

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



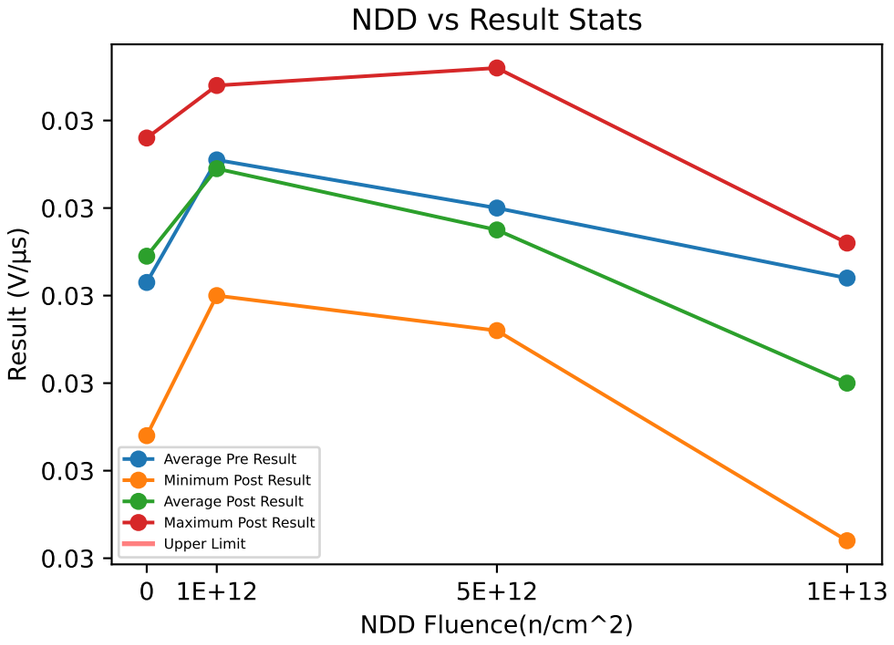
Test Results (Lower Limit = 1.208, Upper Limit = 1.235 (V))

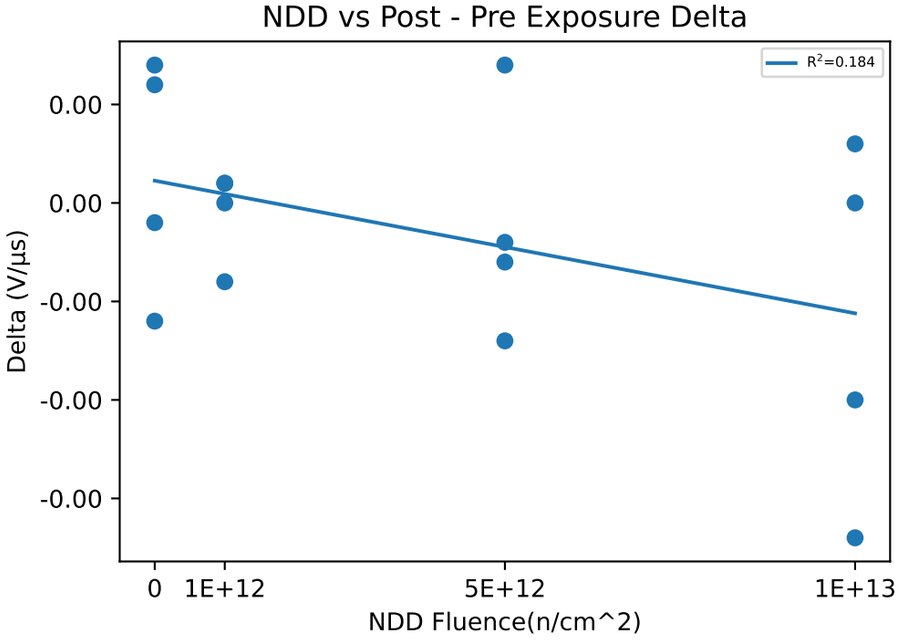
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.2193	1.2186	-0.0007
466	1e+12	NDD	1.2226	1.2213	-0.0013
762	0	CORRELATION	1.2237	1.2231	-0.0006
769	1e+12	NDD	1.2225	1.222	-0.0005
887	1e+12	NDD	1.223	1.2216	-0.0014
891	0	CORRELATION	1.2215	1.2215	0
927	1e+12	NDD	1.2241	1.2236	-0.0005
967	5e+12	NDD	1.2235	1.221	-0.0025
1204	1e+13	NDD	1.2239	1.219	-0.0049
1284	1e+13	NDD	1.2236	1.2181	-0.0055
1292	5e+12	NDD	1.2233	1.2209	-0.0024
1364	1e+13	NDD	1.2226	1.2174	-0.0052
1383	5e+12	NDD	1.2221	1.2194	-0.0027
1388	5e+12	NDD	1.2242	1.2213	-0.0029
1427	1e+13	NDD	1.2204	1.2152	-0.0052
1666	0	CORRELATION	1.2237	1.2236	-0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.2193	1.2221	1.2237	0.0021063	1.2186	1.2217	1.2236	0.0022524	-0.0007	-0.00035	0	0.00035119
1e+12	1.2225	1.223	1.2241	0.00073258	1.2213	1.2221	1.2236	0.0010243	-0.0014	-0.000925	-0.0005	0.00049244
5e+12	1.2221	1.2233	1.2242	0.00087321	1.2194	1.2207	1.2213	0.00085049	-0.0029	-0.002625	-0.0024	0.00022174
1e+13	1.2204	1.2226	1.2239	0.001584	1.2152	1.2174	1.219	0.0016215	-0.0055	-0.0052	-0.0049	0.00024495

Device Test: 22.1 LEVEL|SLOPE_2/RSC_A/4.5/4.5/0/0/4.5/100kHz//@SC_RSC_A_100K





Test Results (No Limits Specified (V/µs))

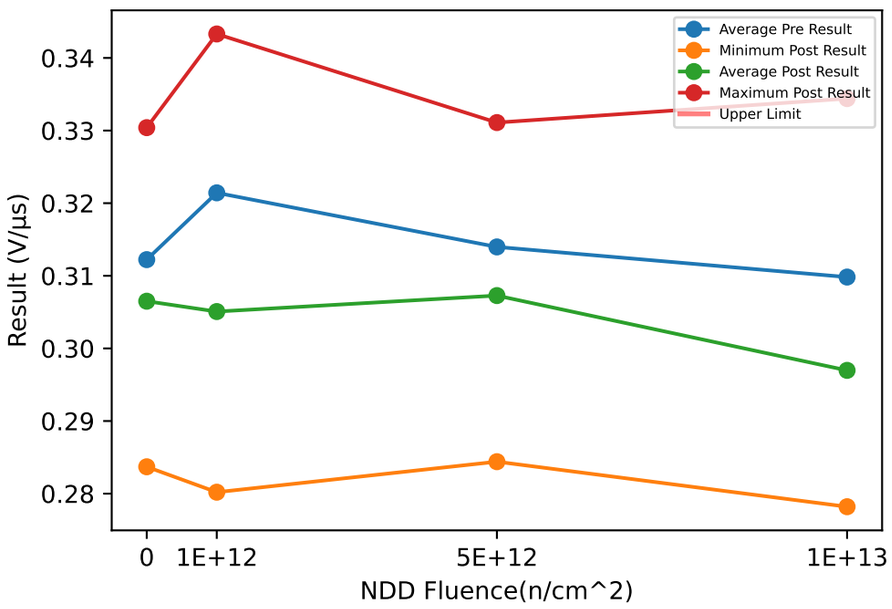
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0294	0.0288	-0.0006
466	1e+12	NDD	0.0279	0.028	0.0001
762	0	CORRELATION	0.0282	0.0289	0.0007
769	1e+12	NDD	0.0286	0.0286	0
887	1e+12	NDD	0.0295	0.0291	-0.0004
891	0	CORRELATION	0.0273	0.0272	-0.0001
927	1e+12	NDD	0.0291	0.0292	0.0001
967	5e+12	NDD	0.0286	0.0293	0.0007
1204	1e+13	NDD	0.0271	0.0274	0.0003
1284	1e+13	NDD	0.0283	0.0266	-0.0017
1292	5e+12	NDD	0.028	0.0278	-0.0002
1364	1e+13	NDD	0.0283	0.0283	0
1383	5e+12	NDD	0.0286	0.0283	-0.0003
1388	5e+12	NDD	0.0288	0.0281	-0.0007
1427	1e+13	NDD	0.0287	0.0277	-0.001
1666	0	CORRELATION	0.0274	0.028	0.0006

Test Statistics (V/µs)

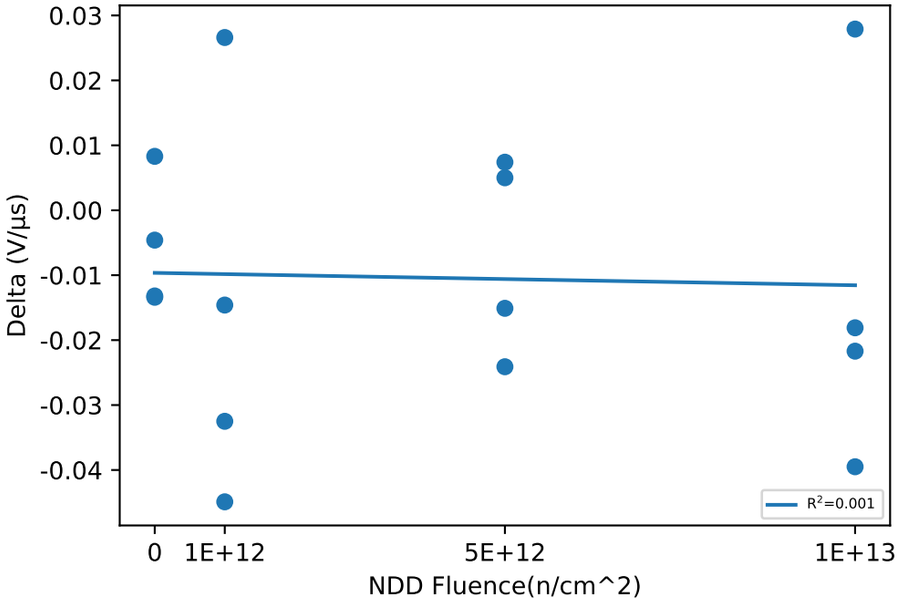
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0273	0.028075	0.0294	0.00097082	0.0272	0.028225	0.0289	0.0007932	-0.0006	0.00015	0.0007	0.00061373
1e+12	0.0279	0.028775	0.0295	0.00068981	0.028	0.028725	0.0292	0.00055	-0.0004	-5e-05	0.0001	0.00023805
5e+12	0.028	0.0285	0.0288	0.00034641	0.0278	0.028375	0.0293	0.00065	-0.0007	-0.000125	0.0007	0.0005909
1e+13	0.0271	0.0281	0.0287	0.00069282	0.0266	0.0275	0.0283	0.00070711	-0.0017	-0.0006	0.0003	0.00092014

Device Test: 22.10 LEVEL|SLOPE_2/RSC_C/5/5/0/0/5/500kHz//@SC_RSC_C_500K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

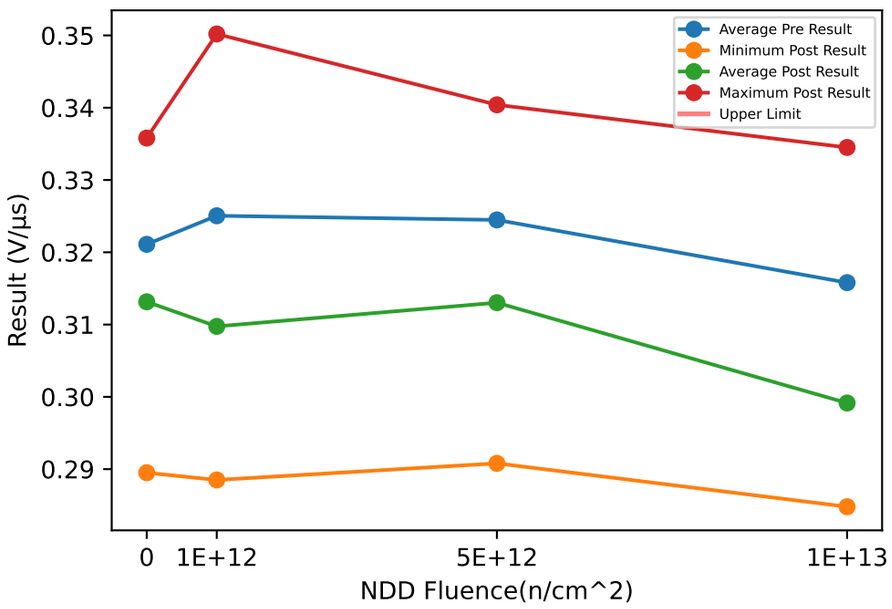
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.3154	0.3237	0.0083
466	1e+12	NDD	0.3251	0.2802	-0.0449
762	0	CORRELATION	0.335	0.3304	-0.0046
769	1e+12	NDD	0.3046	0.29	-0.0146
887	1e+12	NDD	0.3393	0.3068	-0.0325
891	0	CORRELATION	0.3014	0.2882	-0.0132
927	1e+12	NDD	0.3167	0.3433	0.0266
967	5e+12	NDD	0.2995	0.2844	-0.0151
1204	1e+13	NDD	0.3039	0.2858	-0.0181
1284	1e+13	NDD	0.3112	0.2895	-0.0217
1292	5e+12	NDD	0.3135	0.2894	-0.0241
1364	1e+13	NDD	0.3065	0.3344	0.0279
1383	5e+12	NDD	0.3237	0.3311	0.0074
1388	5e+12	NDD	0.3192	0.3242	0.005
1427	1e+13	NDD	0.3177	0.2782	-0.0395
1666	0	CORRELATION	0.2971	0.2837	-0.0134

Test Statistics (V/µs)

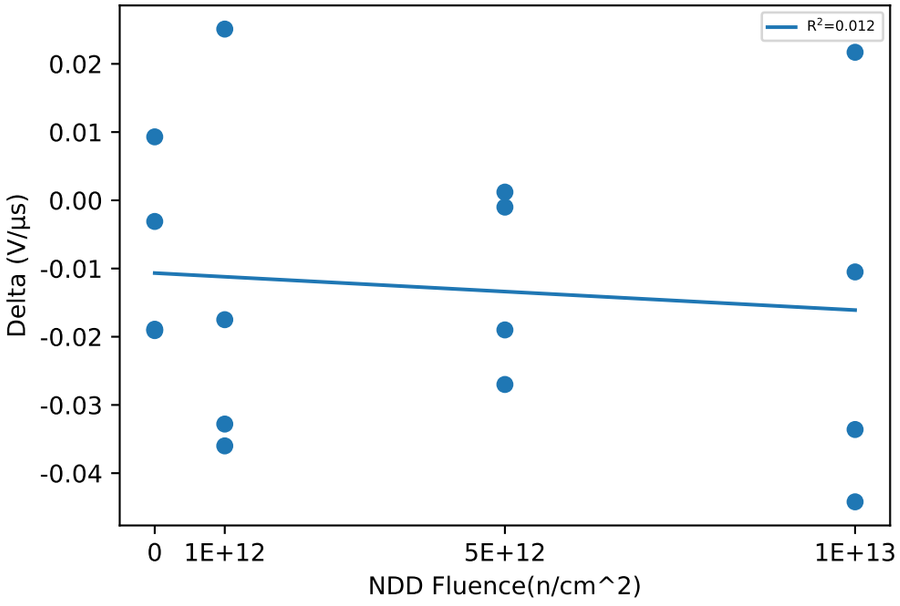
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2971	0.31222	0.335	0.017076	0.2837	0.3065	0.3304	0.023957	-0.0134	-0.005725	0.0083	0.01021
1e+12	0.3046	0.32142	0.3393	0.014588	0.2802	0.30507	0.3433	0.02775	-0.0449	-0.01635	0.0266	0.031218
5e+12	0.2995	0.31398	0.3237	0.010514	0.2844	0.30727	0.3311	0.023783	-0.0241	-0.0067	0.0074	0.015373
1e+13	0.3039	0.30983	0.3177	0.0060572	0.2782	0.29697	0.3344	0.02539	-0.0395	-0.01285	0.0279	0.028733

Device Test: 22.11 LEVEL|SLOPE_2/RSC_C/12/12/0/0/5/500kHz//@SC_RSC_C_500K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

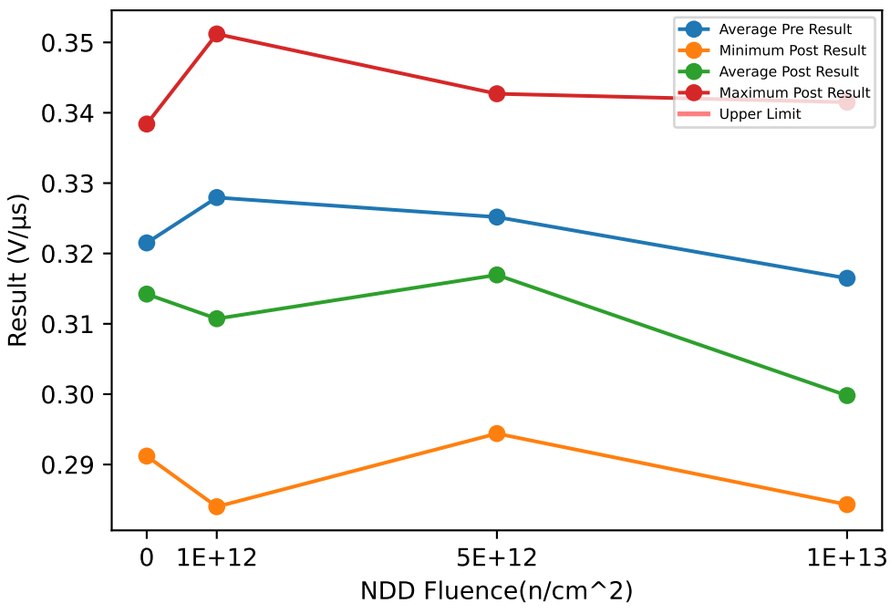
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.3265	0.3358	0.0093
466	1e+12	NDD	0.3245	0.2885	-0.036
762	0	CORRELATION	0.3364	0.3333	-0.0031
769	1e+12	NDD	0.309	0.2915	-0.0175
887	1e+12	NDD	0.3416	0.3088	-0.0328
891	0	CORRELATION	0.3131	0.294	-0.0191
927	1e+12	NDD	0.3251	0.3502	0.0251
967	5e+12	NDD	0.3102	0.2912	-0.019
1204	1e+13	NDD	0.3007	0.2902	-0.0105
1284	1e+13	NDD	0.3207	0.2871	-0.0336
1292	5e+12	NDD	0.3178	0.2908	-0.027
1364	1e+13	NDD	0.3128	0.3345	0.0217
1383	5e+12	NDD	0.3392	0.3404	0.0012
1388	5e+12	NDD	0.3307	0.3297	-0.001
1427	1e+13	NDD	0.329	0.2848	-0.0442
1666	0	CORRELATION	0.3084	0.2895	-0.0189

Test Statistics (V/µs)

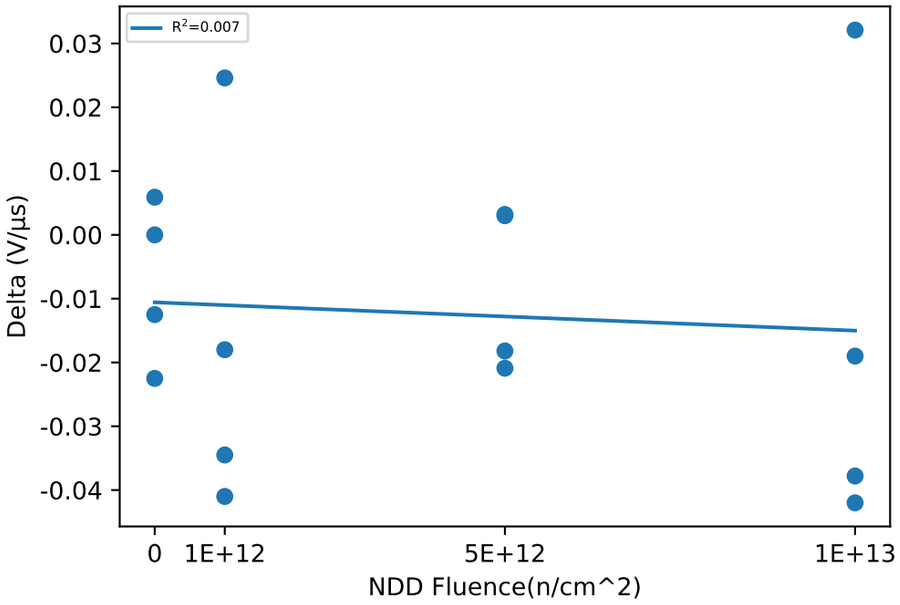
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3084	0.3211	0.3364	0.012761	0.2895	0.31315	0.3358	0.0248	-0.0191	-0.00795	0.0093	0.013727
1e+12	0.309	0.32505	0.3416	0.013314	0.2885	0.30975	0.3502	0.028412	-0.036	-0.0153	0.0251	0.028117
5e+12	0.3102	0.32448	0.3392	0.01296	0.2908	0.31302	0.3404	0.025805	-0.027	-0.01145	0.0012	0.01376
1e+13	0.3007	0.3158	0.329	0.012045	0.2848	0.29915	0.3345	0.02367	-0.0442	-0.01665	0.0217	0.029182

Device Test: 22.12 LEVEL|SLOPE_2/RSC_C/14/14/0/0/5/500kHz//@SC_RSC_C_500K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



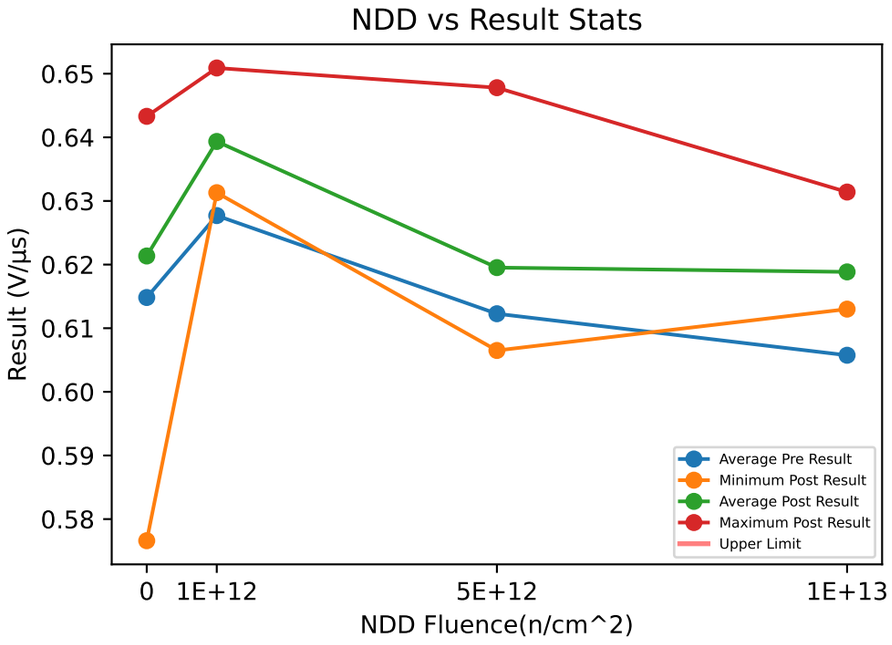
Test Results (No Limits Specified (V/µs))

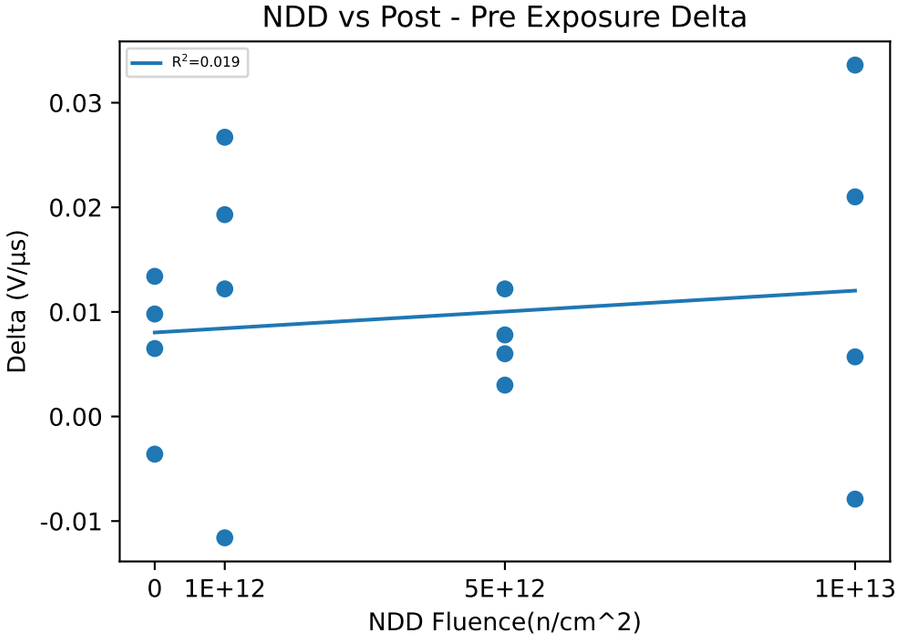
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.3274	0.3333	0.0059
466	1e+12	NDD	0.325	0.284	-0.041
762	0	CORRELATION	0.3384	0.3384	0
769	1e+12	NDD	0.3127	0.2947	-0.018
887	1e+12	NDD	0.3475	0.313	-0.0345
891	0	CORRELATION	0.3165	0.294	-0.0225
927	1e+12	NDD	0.3266	0.3512	0.0246
967	5e+12	NDD	0.3127	0.2945	-0.0182
1204	1e+13	NDD	0.3033	0.2843	-0.019
1284	1e+13	NDD	0.3239	0.2861	-0.0378
1292	5e+12	NDD	0.3153	0.2944	-0.0209
1364	1e+13	NDD	0.3094	0.3415	0.0321
1383	5e+12	NDD	0.3395	0.3427	0.0032
1388	5e+12	NDD	0.3332	0.3362	0.003
1427	1e+13	NDD	0.3293	0.2873	-0.042
1666	0	CORRELATION	0.3037	0.2912	-0.0125

Test Statistics (V/µs)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.3037	0.3215	0.3384	0.014858	0.2912	0.31422	0.3384	0.025083	-0.0225	-0.007275	0.0059	0.012723
1e+12	0.3127	0.32795	0.3475	0.014437	0.284	0.31073	0.3512	0.029521	-0.041	-0.017225	0.0246	0.029516
5e+12	0.3127	0.32517	0.3395	0.0132	0.2944	0.31695	0.3427	0.026116	-0.0209	-0.008225	0.0032	0.013124
1e+13	0.3033	0.31648	0.3293	0.012155	0.2843	0.2998	0.3415	0.027827	-0.042	-0.016675	0.0321	0.03402

Device Test: 22.13 LEVEL|SLOPE_2/RSC_D/4.5/4.5/0/0/4.5/1MHz//@SC_RSC_D_1M





Test Results (No Limits Specified (V/µs))

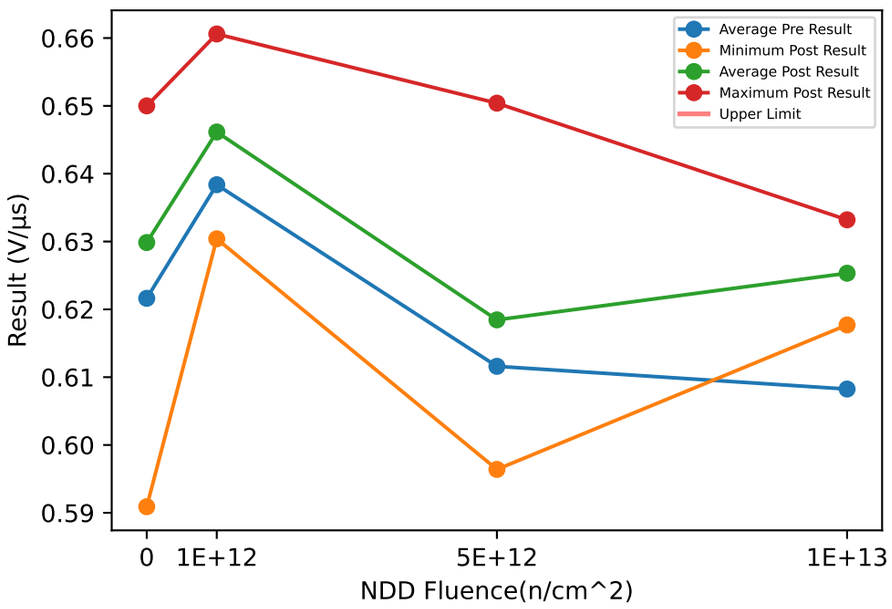
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5802	0.5766	-0.0036
466	1e+12	NDD	0.612	0.6313	0.0193
762	0	CORRELATION	0.6149	0.6283	0.0134
769	1e+12	NDD	0.6387	0.6509	0.0122
887	1e+12	NDD	0.609	0.6357	0.0267
891	0	CORRELATION	0.6368	0.6433	0.0065
927	1e+12	NDD	0.6511	0.6395	-0.0116
967	5e+12	NDD	0.6356	0.6478	0.0122
1204	1e+13	NDD	0.6092	0.6149	0.0057
1284	1e+13	NDD	0.592	0.613	0.021
1292	5e+12	NDD	0.6005	0.6065	0.006
1364	1e+13	NDD	0.624	0.6161	-0.0079
1383	5e+12	NDD	0.6066	0.6144	0.0078
1388	5e+12	NDD	0.6064	0.6094	0.003
1427	1e+13	NDD	0.5978	0.6314	0.0336
1666	0	CORRELATION	0.6274	0.6372	0.0098

Test Statistics (V/µs)

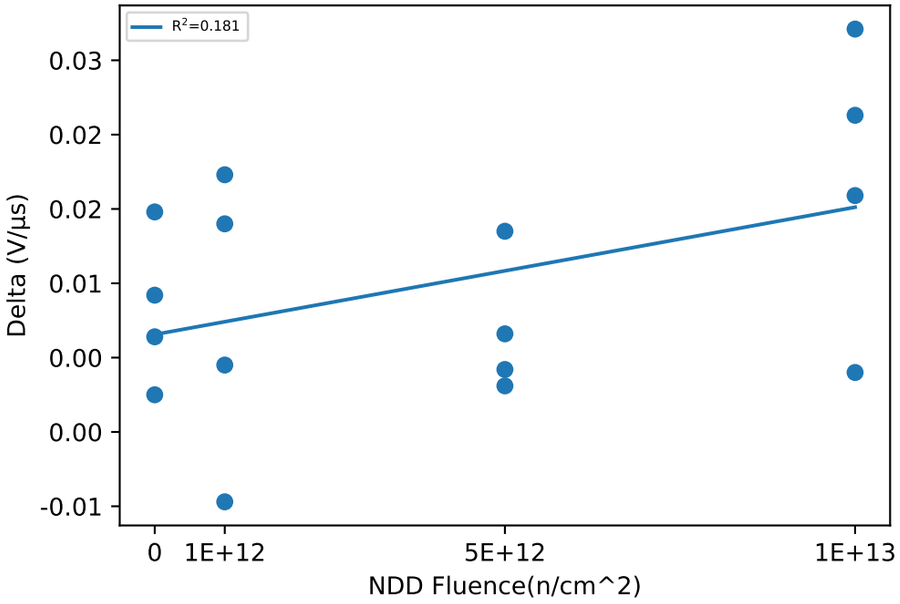
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5802	0.61482	0.6368	0.024765	0.5766	0.62135	0.6433	0.030462	-0.0036	0.006525	0.0134	0.0073145
1e+12	0.609	0.6277	0.6511	0.020532	0.6313	0.63935	0.6509	0.0083974	-0.0116	0.01165	0.0267	0.016592
5e+12	0.6005	0.61228	0.6356	0.015805	0.6065	0.61952	0.6478	0.01913	0.003	0.00725	0.0122	0.0038484
1e+13	0.592	0.60575	0.624	0.014109	0.613	0.61885	0.6314	0.0084635	-0.0079	0.0131	0.0336	0.018059

Device Test: 22.14 LEVEL|SLOPE_2/RSC_D/5/5/0/0/5/1MHz//@SC_RSC_D_1M

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

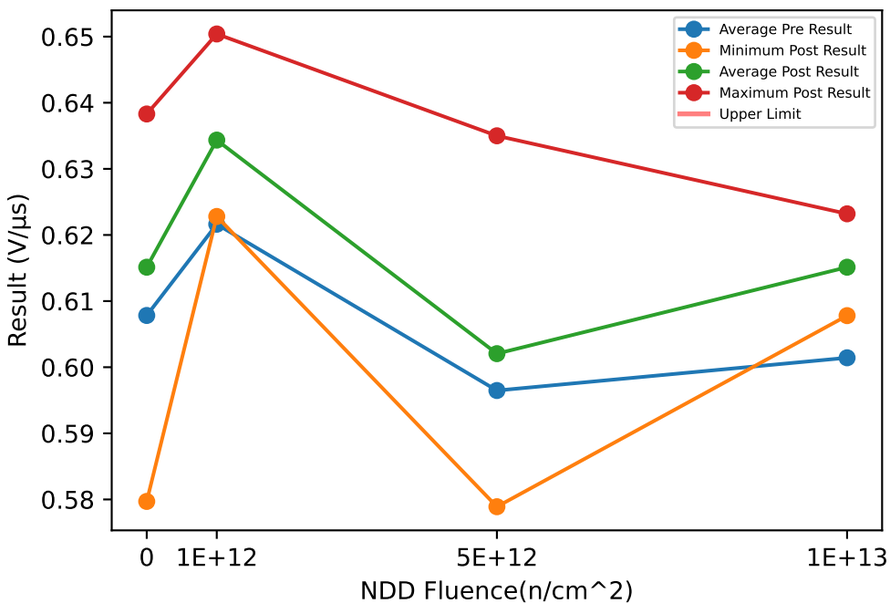
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5845	0.5909	0.0064
466	1e+12	NDD	0.6164	0.6304	0.014
762	0	CORRELATION	0.6255	0.6347	0.0092
769	1e+12	NDD	0.6561	0.6606	0.0045
887	1e+12	NDD	0.6265	0.6438	0.0173
891	0	CORRELATION	0.6475	0.65	0.0025
927	1e+12	NDD	0.6545	0.6498	-0.0047
967	5e+12	NDD	0.6369	0.6504	0.0135
1204	1e+13	NDD	0.6078	0.6237	0.0159
1284	1e+13	NDD	0.5906	0.6177	0.0271
1292	5e+12	NDD	0.5933	0.5964	0.0031
1364	1e+13	NDD	0.6227	0.6267	0.004
1383	5e+12	NDD	0.6053	0.6095	0.0042
1388	5e+12	NDD	0.6109	0.6175	0.0066
1427	1e+13	NDD	0.6119	0.6332	0.0213
1666	0	CORRELATION	0.629	0.6438	0.0148

Test Statistics (V/µs)

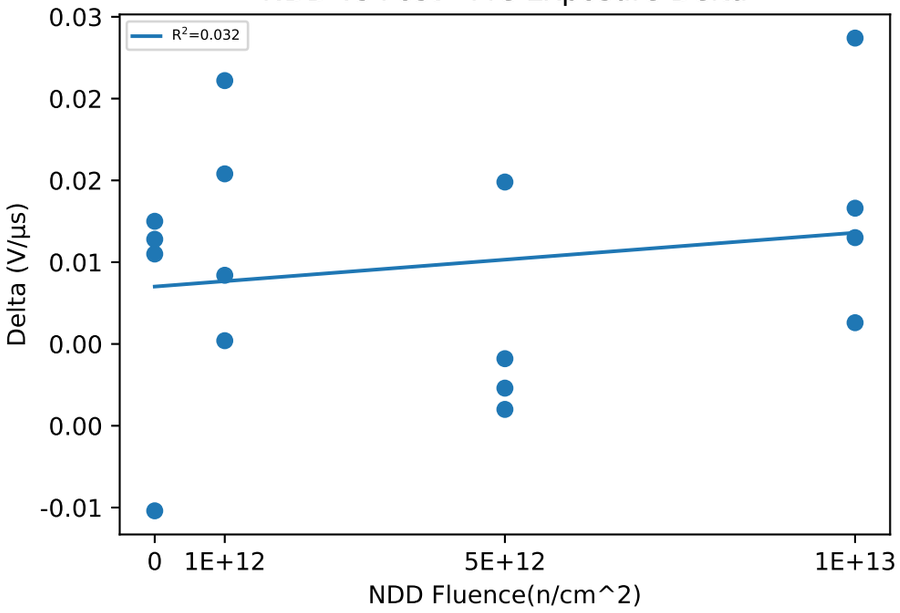
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5845	0.62162	0.6475	0.026566	0.5909	0.62985	0.65	0.026716	0.0025	0.008225	0.0148	0.0051732
1e+12	0.6164	0.63837	0.6561	0.019984	0.6304	0.64615	0.6606	0.012592	-0.0047	0.007775	0.0173	0.0099302
5e+12	0.5933	0.6116	0.6369	0.018395	0.5964	0.61845	0.6504	0.023007	0.0031	0.00685	0.0135	0.004668
1e+13	0.5906	0.60825	0.6227	0.01334	0.6177	0.62533	0.6332	0.0064469	0.004	0.017075	0.0271	0.0098436

Device Test: 22.15 LEVEL|SLOPE_2/RSC_D/12/12/0/0/5/1MHz//@SC_RSC_D_1M

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

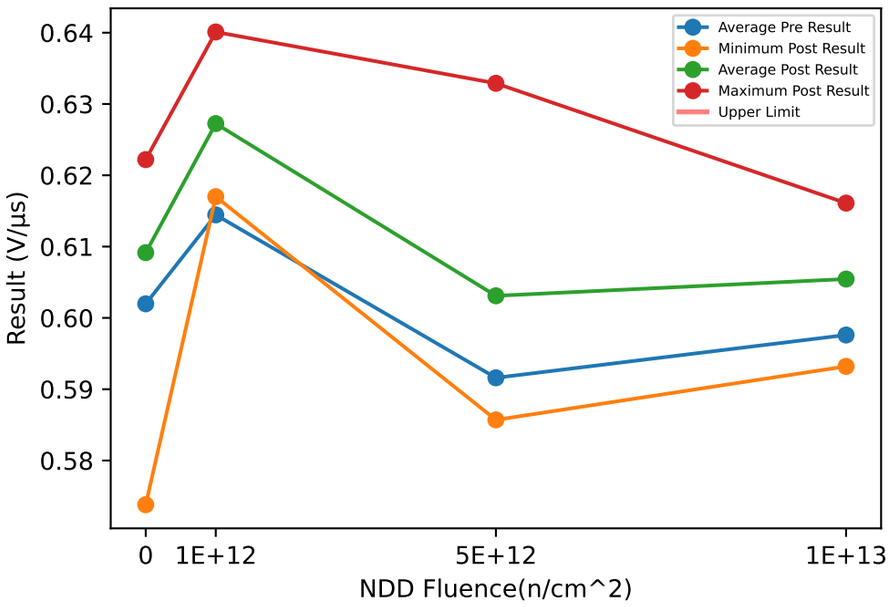
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5683	0.5797	0.0114
466	1e+12	NDD	0.6017	0.6228	0.0211
762	0	CORRELATION	0.6242	0.619	-0.0052
769	1e+12	NDD	0.635	0.6504	0.0154
887	1e+12	NDD	0.6227	0.6279	0.0052
891	0	CORRELATION	0.6278	0.6383	0.0105
927	1e+12	NDD	0.6271	0.6363	0.0092
967	5e+12	NDD	0.6201	0.635	0.0149
1204	1e+13	NDD	0.5963	0.6078	0.0115
1284	1e+13	NDD	0.5854	0.6091	0.0237
1292	5e+12	NDD	0.5779	0.5789	0.001
1364	1e+13	NDD	0.6141	0.6204	0.0063
1383	5e+12	NDD	0.5943	0.5966	0.0023
1388	5e+12	NDD	0.5936	0.5977	0.0041
1427	1e+13	NDD	0.6099	0.6232	0.0133
1666	0	CORRELATION	0.611	0.6235	0.0125

Test Statistics (V/µs)

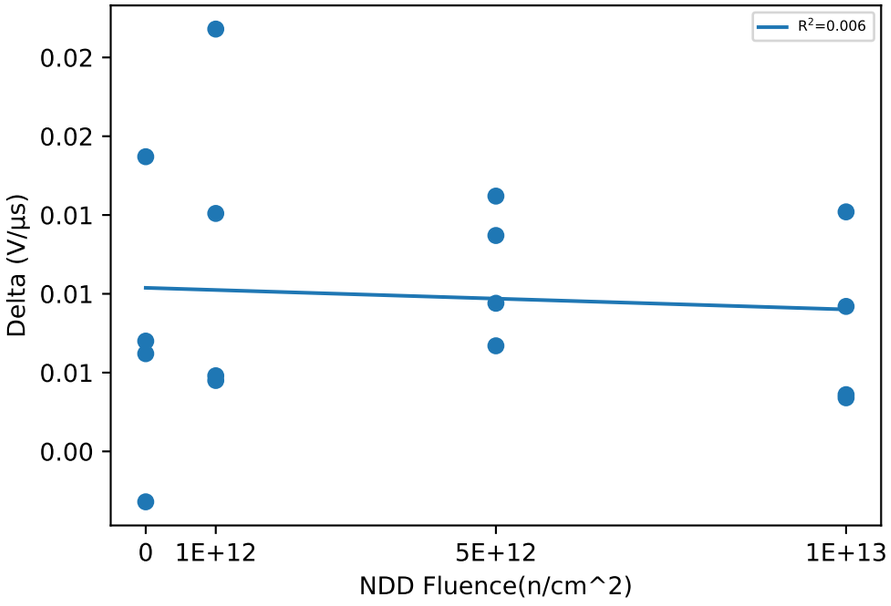
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5683	0.60783	0.6278	0.027322	0.5797	0.61513	0.6383	0.025014	-0.0052	0.0073	0.0125	0.0083734
1e+12	0.6017	0.62162	0.635	0.014225	0.6228	0.63435	0.6504	0.012061	0.0052	0.012725	0.0211	0.0069844
5e+12	0.5779	0.59647	0.6201	0.017475	0.5789	0.60205	0.635	0.023596	0.001	0.005575	0.0149	0.0063453
1e+13	0.5854	0.60142	0.6141	0.013109	0.6078	0.61512	0.6232	0.00781	0.0063	0.0137	0.0237	0.0072975

Device Test: 22.16 LEVEL|SLOPE_2/RSC_D/14/14/0/0/5/1MHz//@SC_RSC_D_1M

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

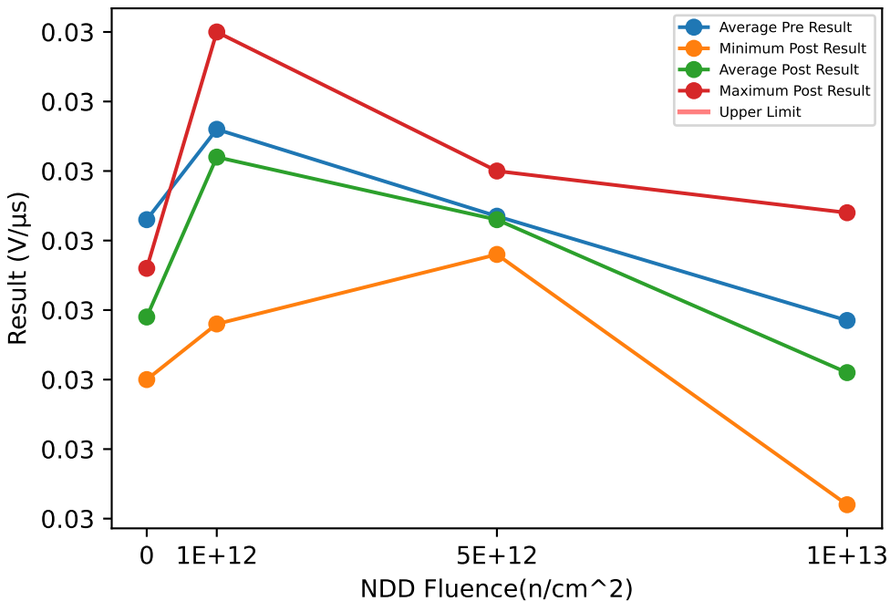
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5668	0.5738	0.007
466	1e+12	NDD	0.5936	0.6204	0.0268
762	0	CORRELATION	0.6133	0.6195	0.0062
769	1e+12	NDD	0.625	0.6401	0.0151
887	1e+12	NDD	0.6122	0.617	0.0048
891	0	CORRELATION	0.6254	0.6222	-0.0032
927	1e+12	NDD	0.627	0.6315	0.0045
967	5e+12	NDD	0.6167	0.6329	0.0162
1204	1e+13	NDD	0.5898	0.5932	0.0034
1284	1e+13	NDD	0.5815	0.5967	0.0152
1292	5e+12	NDD	0.572	0.5857	0.0137
1364	1e+13	NDD	0.6069	0.6161	0.0092
1383	5e+12	NDD	0.5863	0.5957	0.0094
1388	5e+12	NDD	0.5914	0.5981	0.0067
1427	1e+13	NDD	0.6122	0.6158	0.0036
1666	0	CORRELATION	0.6024	0.6211	0.0187

Test Statistics (V/µs)

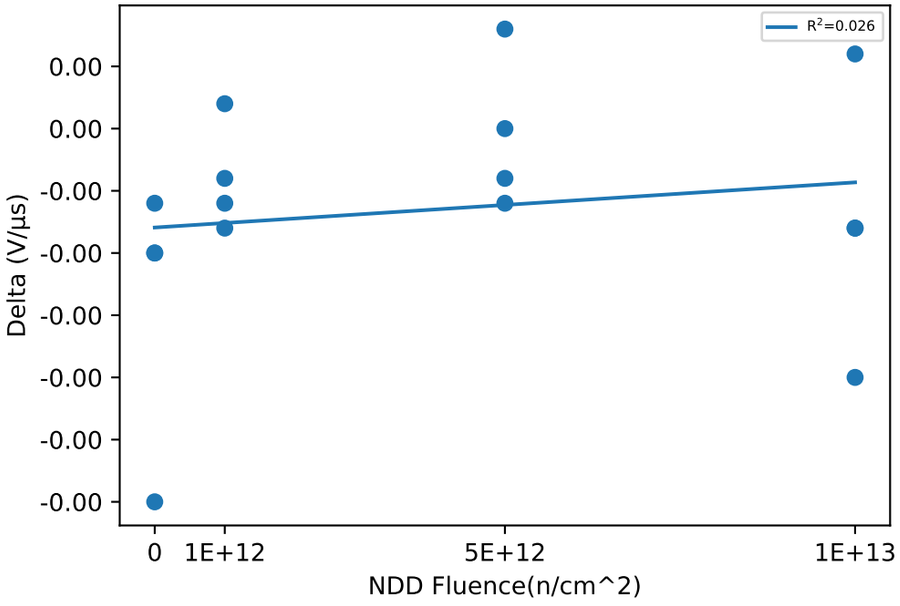
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5668	0.60197	0.6254	0.025262	0.5738	0.60915	0.6222	0.023593	-0.0032	0.007175	0.0187	0.0089712
1e+12	0.5936	0.61445	0.627	0.015369	0.617	0.62725	0.6401	0.01057	0.0045	0.0128	0.0268	0.010554
5e+12	0.572	0.5916	0.6167	0.01864	0.5857	0.6031	0.6329	0.02058	0.0067	0.0115	0.0162	0.0042575
1e+13	0.5815	0.5976	0.6122	0.014372	0.5932	0.60545	0.6161	0.012209	0.0034	0.00785	0.0152	0.005589

Device Test: 22.2 LEVEL|SLOPE_2/RSC_A/5/5/0/0/5/100kHz//@SC_RSC_A_100K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

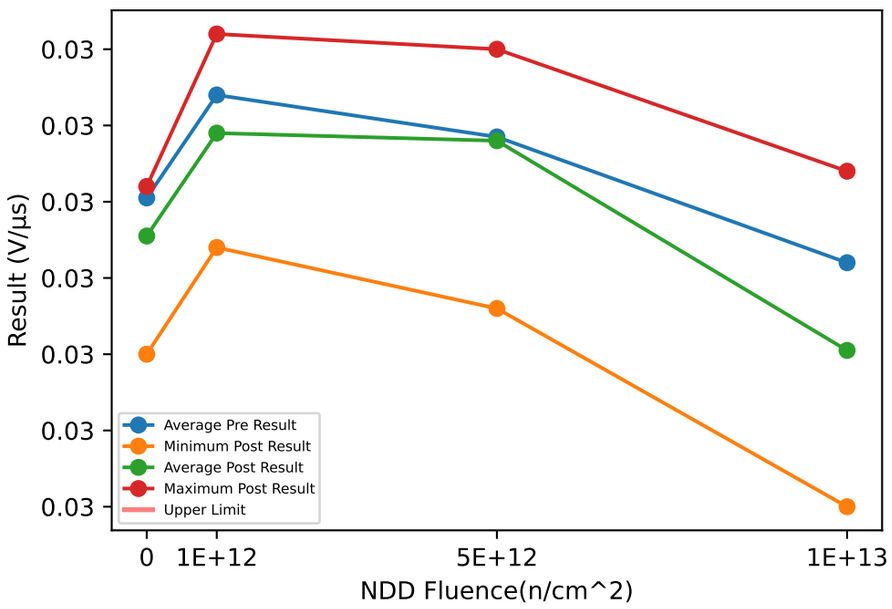
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0295	0.028	-0.0015
466	1e+12	NDD	0.0283	0.0279	-0.0004
762	0	CORRELATION	0.0283	0.028	-0.0003
769	1e+12	NDD	0.029	0.0288	-0.0002
887	1e+12	NDD	0.03	0.0297	-0.0003
891	0	CORRELATION	0.028	0.0275	-0.0005
927	1e+12	NDD	0.0299	0.03	0.0001
967	5e+12	NDD	0.0292	0.029	-0.0002
1204	1e+13	NDD	0.0272	0.0268	-0.0004
1284	1e+13	NDD	0.0276	0.0266	-0.001
1292	5e+12	NDD	0.028	0.0284	0.0004
1364	1e+13	NDD	0.0284	0.0287	0.0003
1383	5e+12	NDD	0.0287	0.0284	-0.0003
1388	5e+12	NDD	0.0288	0.0288	0
1427	1e+13	NDD	0.0285	0.0281	-0.0004
1666	0	CORRELATION	0.0288	0.0283	-0.0005

Test Statistics (V/µs)

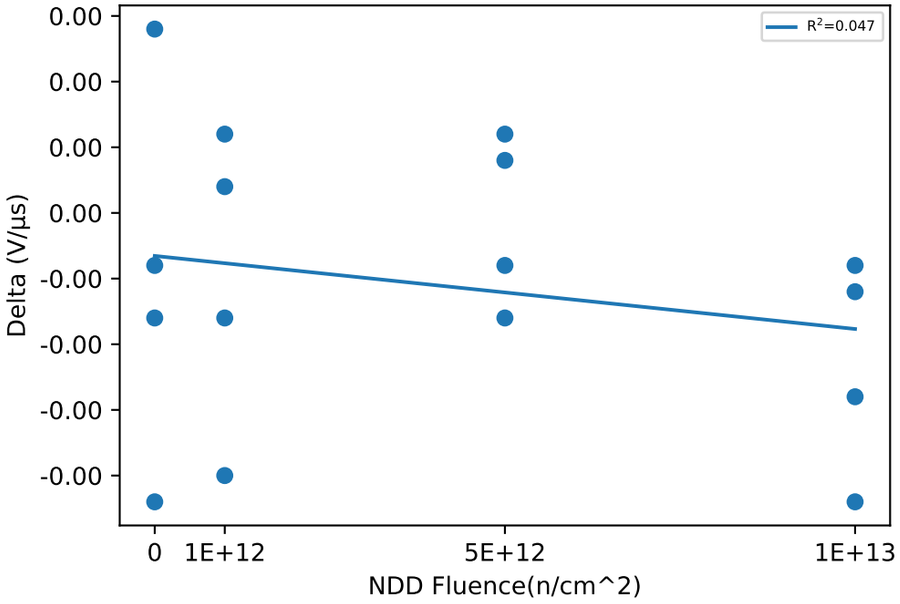
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.028	0.02865	0.0295	0.00065574	0.0275	0.02795	0.0283	0.00033166	-0.0015	-0.0007	-0.0003	0.0005416
1e+12	0.0283	0.0293	0.03	0.00080416	0.0279	0.0291	0.03	0.00094868	-0.0004	-0.0002	0.0001	0.00021602
5e+12	0.028	0.028675	0.0292	0.00049917	0.0284	0.02865	0.029	0.0003	-0.0003	-2.5e-05	0.0004	0.00030957
1e+13	0.0272	0.027925	0.0285	0.00062915	0.0266	0.02755	0.0287	0.0010149	-0.001	-0.000375	0.0003	0.00053151

Device Test: 22.3 LEVEL|SLOPE_2/RSC_A/12/12/0/0/5/100kHz//@SC_RSC_A_100K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

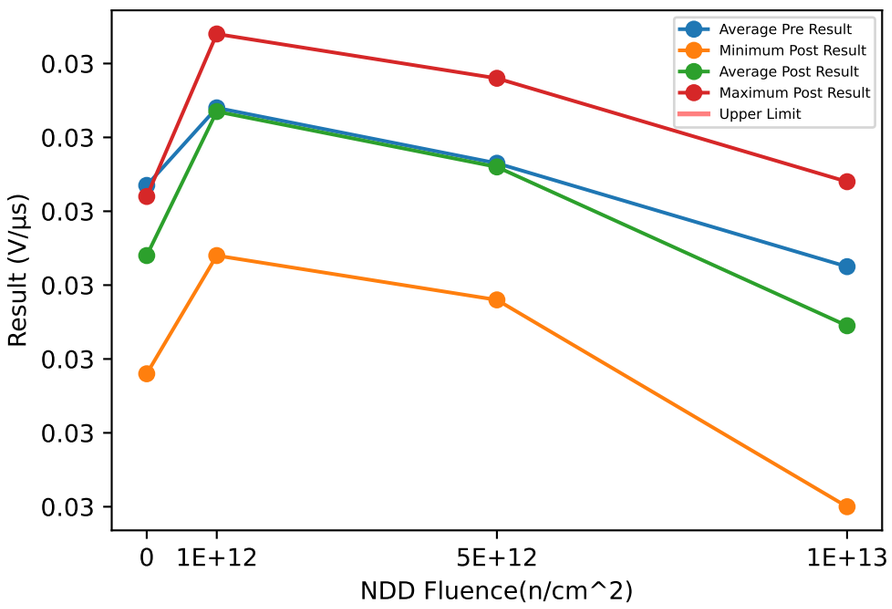
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0292	0.0281	-0.0011
466	1e+12	NDD	0.0281	0.0277	-0.0004
762	0	CORRELATION	0.0281	0.0279	-0.0002
769	1e+12	NDD	0.0283	0.0284	0.0001
887	1e+12	NDD	0.0296	0.0286	-0.001
891	0	CORRELATION	0.0274	0.027	-0.0004
927	1e+12	NDD	0.0288	0.0291	0.0003
967	5e+12	NDD	0.0294	0.029	-0.0004
1204	1e+13	NDD	0.0267	0.026	-0.0007
1284	1e+13	NDD	0.0273	0.0262	-0.0011
1292	5e+12	NDD	0.0271	0.0273	0.0002
1364	1e+13	NDD	0.028	0.0277	-0.0003
1383	5e+12	NDD	0.0282	0.0285	0.0003
1388	5e+12	NDD	0.029	0.0288	-0.0002
1427	1e+13	NDD	0.0284	0.0282	-0.0002
1666	0	CORRELATION	0.0274	0.0281	0.0007

Test Statistics (V/µs)

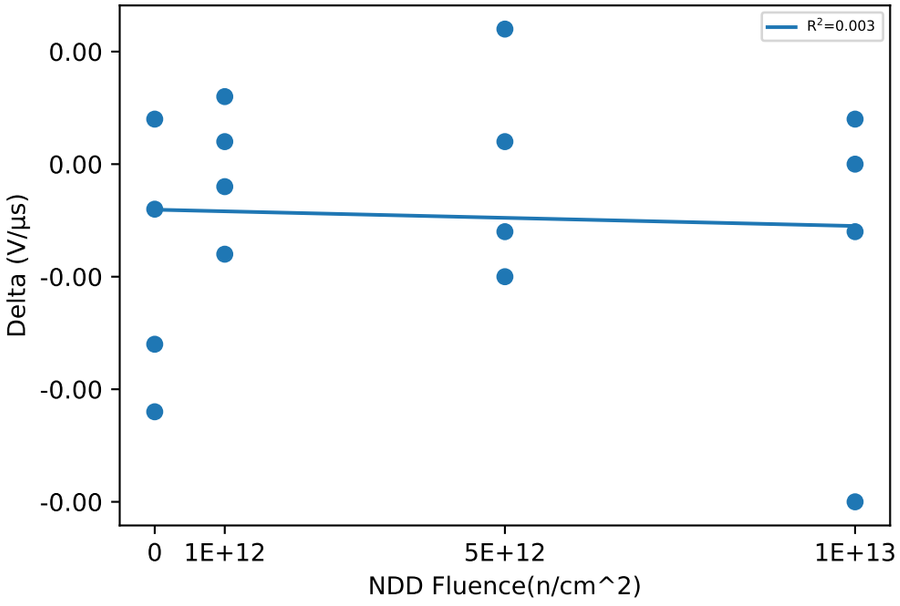
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0274	0.028025	0.0292	0.00085	0.027	0.027775	0.0281	0.0005252	-0.0011	-0.00025	0.0007	0.00074162
1e+12	0.0281	0.0287	0.0296	0.00066833	0.0277	0.02845	0.0291	0.00058023	-0.001	-0.00025	0.0003	0.00058023
5e+12	0.0271	0.028425	0.0294	0.0010145	0.0273	0.0284	0.029	0.00076158	-0.0004	-2.5e-05	0.0003	0.0003304
1e+13	0.0267	0.0276	0.0284	0.00075277	0.026	0.027025	0.0282	0.0010905	-0.0011	-0.000575	-0.0002	0.0004113

Device Test: 22.4 LEVEL|SLOPE_2/RSC_A/14/14/0/0/5/100kHz//@SC_RSC_A_100K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



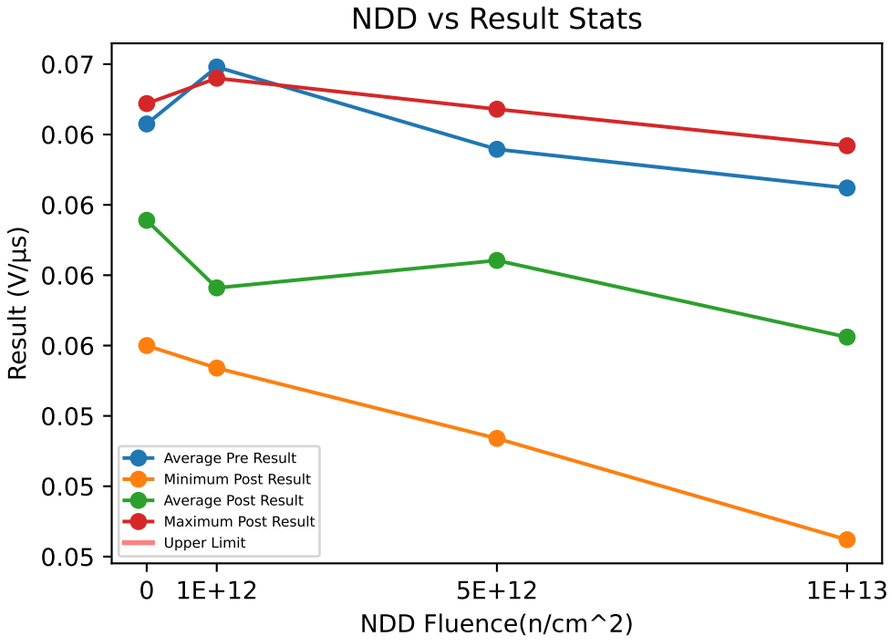
Test Results (No Limits Specified (V/µs))

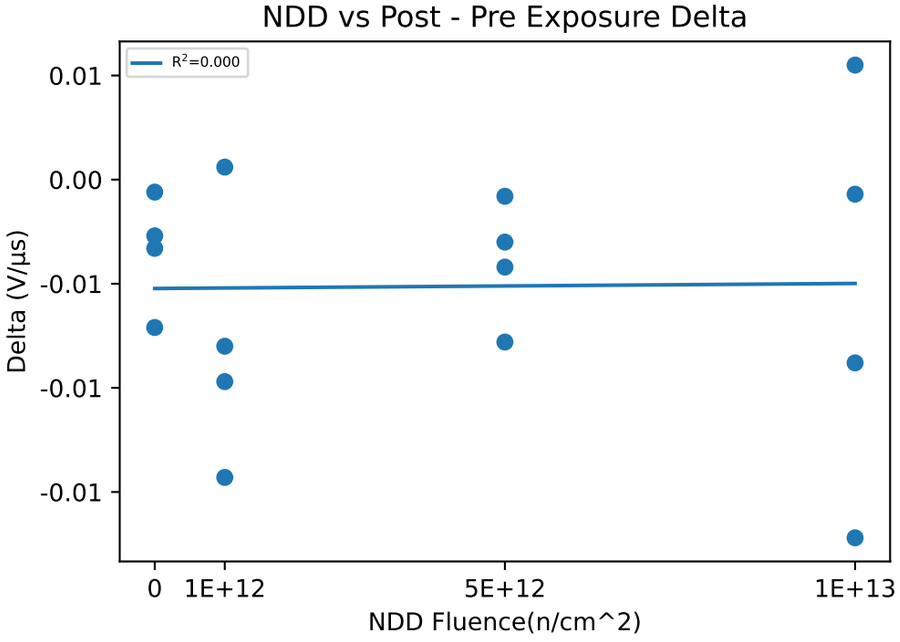
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0292	0.0281	-0.0011
466	1e+12	NDD	0.0278	0.0277	-0.0001
762	0	CORRELATION	0.0278	0.028	0.0002
769	1e+12	NDD	0.0286	0.0287	0.0001
887	1e+12	NDD	0.0295	0.0291	-0.0004
891	0	CORRELATION	0.0277	0.0269	-0.0008
927	1e+12	NDD	0.0289	0.0292	0.0003
967	5e+12	NDD	0.0292	0.0289	-0.0003
1204	1e+13	NDD	0.0269	0.0266	-0.0003
1284	1e+13	NDD	0.0275	0.026	-0.0015
1292	5e+12	NDD	0.0268	0.0274	0.0006
1364	1e+13	NDD	0.0281	0.0281	0
1383	5e+12	NDD	0.0283	0.0284	0.0001
1388	5e+12	NDD	0.029	0.0285	-0.0005
1427	1e+13	NDD	0.028	0.0282	0.0002
1666	0	CORRELATION	0.028	0.0278	-0.0002

Test Statistics (V/µs)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0277	0.028175	0.0292	0.00069462	0.0269	0.0277	0.0281	0.00054772	-0.0011	-0.000475	0.0002	0.00058523
1e+12	0.0278	0.0287	0.0295	0.00070711	0.0277	0.028675	0.0292	0.00068496	-0.0004	-2.5e-05	0.0003	0.00029861
5e+12	0.0268	0.028325	0.0292	0.0010874	0.0274	0.0283	0.0289	0.0006377	-0.0005	-2.5e-05	0.0006	0.00048563
1e+13	0.0269	0.027625	0.0281	0.00055	0.026	0.027225	0.0282	0.0010966	-0.0015	-0.0004	0.0002	0.00076158

Device Test: 22.5 LEVEL|SLOPE_2/RSC_B/4.5/4.5/0/0/4.5/200kHz//@SC_RSC_B_200K





Test Results (No Limits Specified (V/µs))

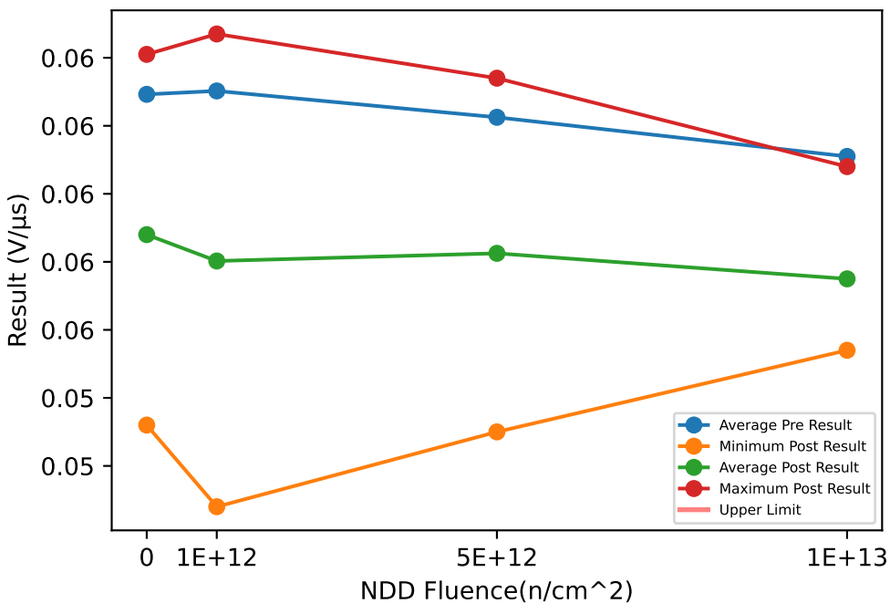
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0663	0.0636	-0.0027
466	1e+12	NDD	0.0639	0.0542	-0.0097
762	0	CORRELATION	0.0648	0.0615	-0.0033
769	1e+12	NDD	0.0631	0.0551	-0.008
887	1e+12	NDD	0.0687	0.0544	-0.0143
891	0	CORRELATION	0.0583	0.0577	-0.0006
927	1e+12	NDD	0.0639	0.0645	0.0006
967	5e+12	NDD	0.0595	0.0517	-0.0078
1204	1e+13	NDD	0.0588	0.0581	-0.0007
1284	1e+13	NDD	0.0653	0.0481	-0.0172
1292	5e+12	NDD	0.0584	0.0554	-0.003
1364	1e+13	NDD	0.0566	0.0621	0.0055
1383	5e+12	NDD	0.0676	0.0634	-0.0042
1388	5e+12	NDD	0.0624	0.0616	-0.0008
1427	1e+13	NDD	0.0617	0.0529	-0.0088
1666	0	CORRELATION	0.0621	0.055	-0.0071

Test Statistics (V/µs)

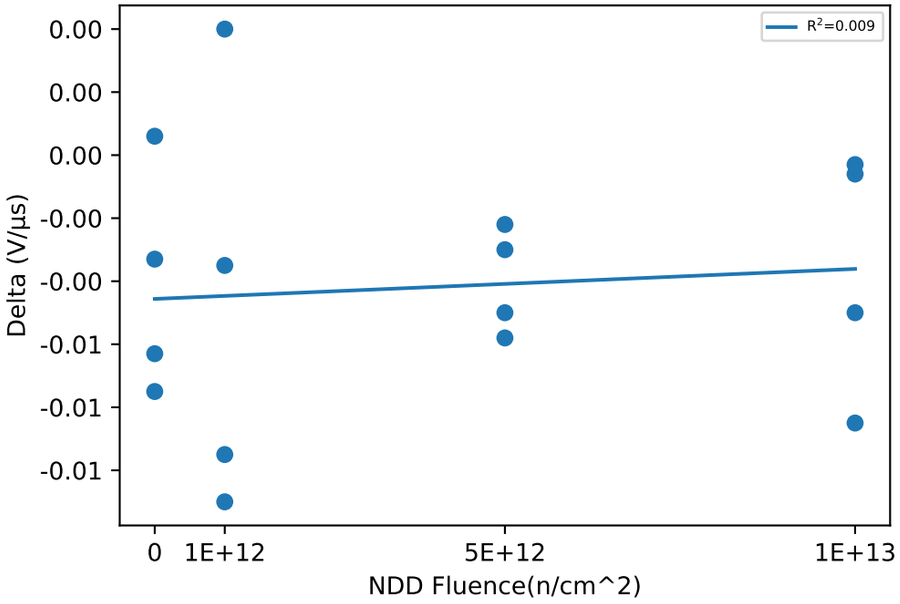
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0583	0.062875	0.0663	0.0035103	0.055	0.05945	0.0636	0.0038423	-0.0071	-0.003425	-0.0006	0.0027097
1e+12	0.0631	0.0649	0.0687	0.0025612	0.0542	0.05705	0.0645	0.0049816	-0.0143	-0.00785	0.0006	0.0062303
5e+12	0.0584	0.061975	0.0676	0.0041121	0.0517	0.058025	0.0634	0.0054335	-0.0078	-0.00395	-0.0008	0.0029275
1e+13	0.0566	0.0606	0.0653	0.0037656	0.0481	0.0553	0.0621	0.0061014	-0.0172	-0.0053	0.0055	0.00986

Device Test: 22.6 LEVEL|SLOPE_2/RSC_B/5/5/0/0/5/200kHz//@SC_RSC_B_200K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

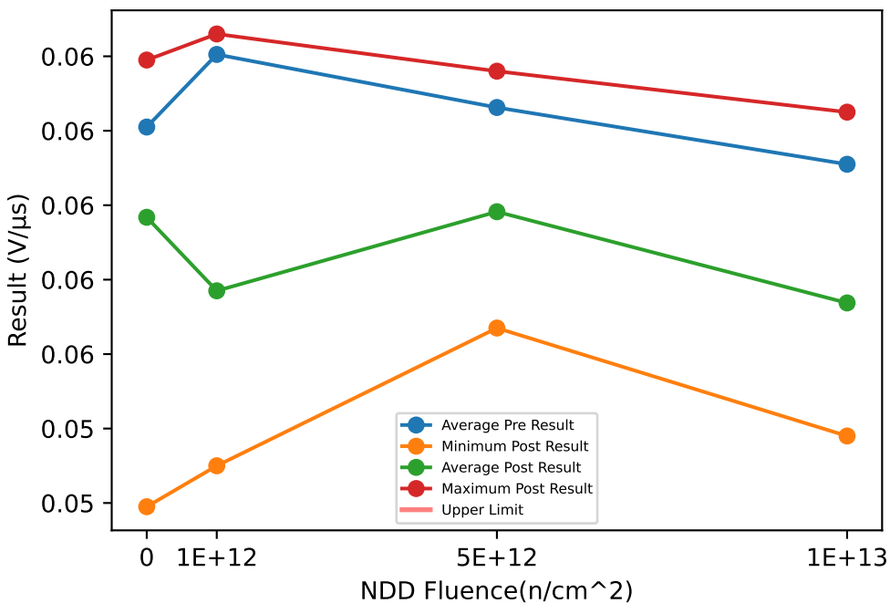
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0635	0.0641	0.0006
466	1e+12	NDD	0.0618	0.0508	-0.011
762	0	CORRELATION	0.0655	0.0622	-0.0033
769	1e+12	NDD	0.062	0.0585	-0.0035
887	1e+12	NDD	0.0676	0.0581	-0.0095
891	0	CORRELATION	0.0632	0.0557	-0.0075
927	1e+12	NDD	0.0607	0.0647	0.004
967	5e+12	NDD	0.0569	0.0547	-0.0022
1204	1e+13	NDD	0.0567	0.0564	-0.0003
1284	1e+13	NDD	0.0639	0.0554	-0.0085
1292	5e+12	NDD	0.0588	0.053	-0.0058
1364	1e+13	NDD	0.0614	0.0608	-0.0006
1383	5e+12	NDD	0.0664	0.0634	-0.003
1388	5e+12	NDD	0.0669	0.0619	-0.005
1427	1e+13	NDD	0.0624	0.0574	-0.005
1666	0	CORRELATION	0.0595	0.0532	-0.0063

Test Statistics (V/µs)

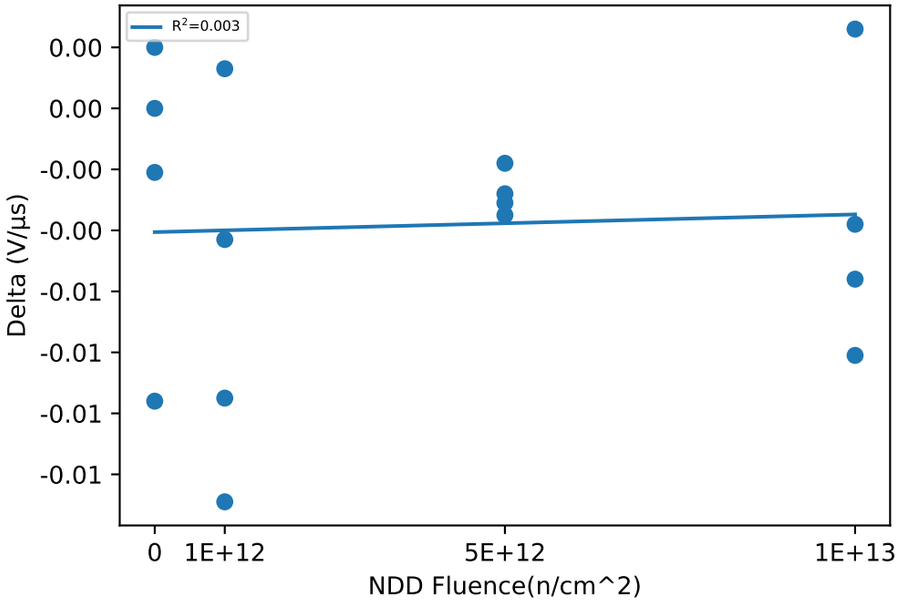
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0595	0.062925	0.0655	0.0025012	0.0532	0.0588	0.0641	0.0051839	-0.0075	-0.004125	0.0006	0.0036114
1e+12	0.0607	0.063025	0.0676	0.0031031	0.0508	0.058025	0.0647	0.0056859	-0.011	-0.005	0.004	0.0068191
5e+12	0.0569	0.06225	0.0669	0.0051436	0.053	0.05825	0.0634	0.0051643	-0.0058	-0.004	-0.0022	0.0016813
1e+13	0.0567	0.0611	0.0639	0.0031081	0.0554	0.0575	0.0608	0.0023466	-0.0085	-0.0036	-0.0003	0.0039098

Device Test: 22.7 LEVEL|SLOPE_2/RSC_B/12/12/0/0/5/200kHz//@SC_RSC_B_200K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

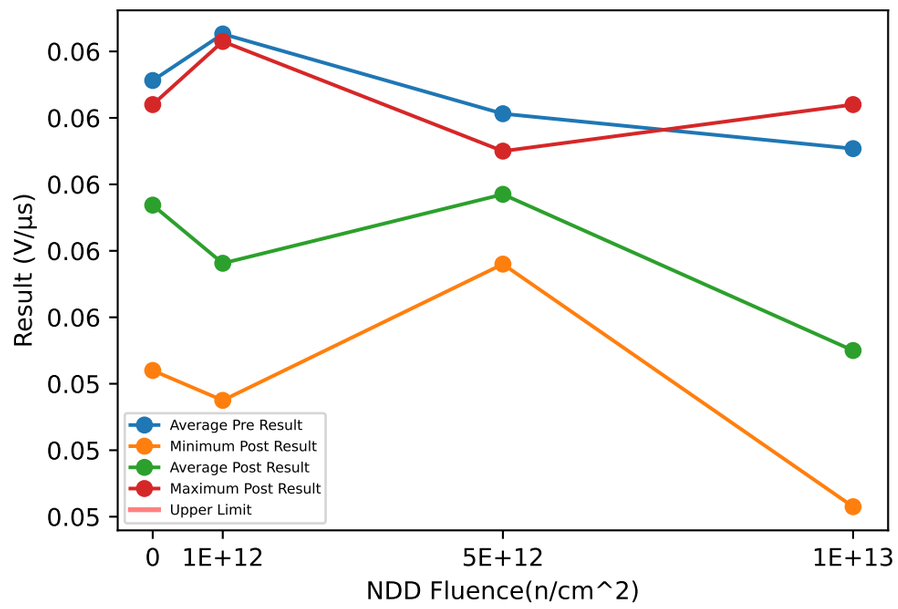
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0639	0.0639	0
466	1e+12	NDD	0.0625	0.053	-0.0095
762	0	CORRELATION	0.0643	0.0622	-0.0021
769	1e+12	NDD	0.0629	0.0586	-0.0043
887	1e+12	NDD	0.0675	0.0546	-0.0129
891	0	CORRELATION	0.0587	0.0607	0.002
927	1e+12	NDD	0.0633	0.0646	0.0013
967	5e+12	NDD	0.0603	0.0575	-0.0028
1204	1e+13	NDD	0.0594	0.0538	-0.0056
1284	1e+13	NDD	0.0631	0.0593	-0.0038
1292	5e+12	NDD	0.0602	0.0567	-0.0035
1364	1e+13	NDD	0.0599	0.0625	0.0026
1383	5e+12	NDD	0.0667	0.0636	-0.0031
1388	5e+12	NDD	0.0633	0.0615	-0.0018
1427	1e+13	NDD	0.062	0.0539	-0.0081
1666	0	CORRELATION	0.0615	0.0519	-0.0096

Test Statistics (V/µs)

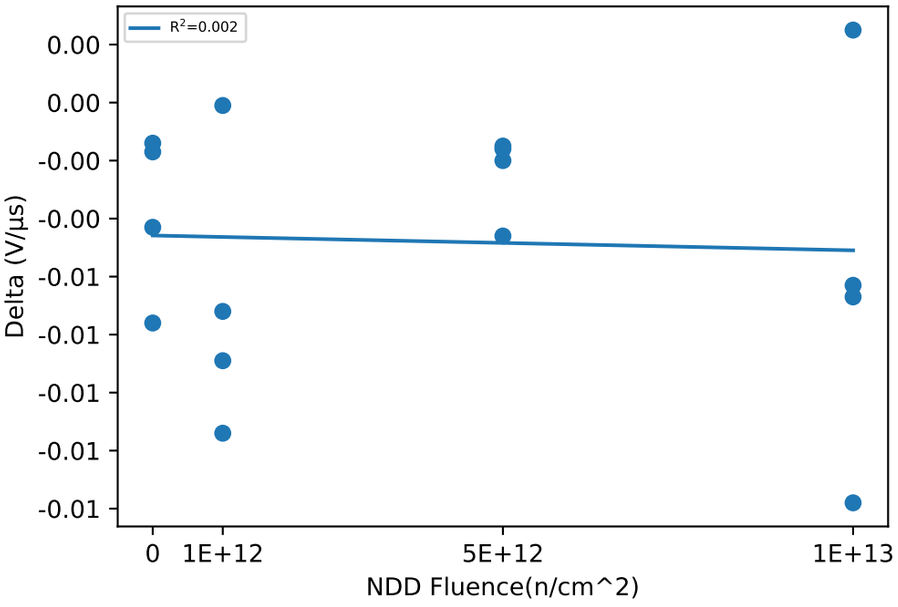
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0587	0.0621	0.0643	0.002582	0.0519	0.059675	0.0639	0.0053456	-0.0096	-0.002425	0.002	0.0050678
1e+12	0.0625	0.06405	0.0675	0.0023231	0.053	0.0577	0.0646	0.0051678	-0.0129	-0.00635	0.0013	0.0062062
5e+12	0.0602	0.062625	0.0667	0.0030739	0.0567	0.059825	0.0636	0.0032776	-0.0035	-0.0028	-0.0018	0.00072572
1e+13	0.0594	0.0611	0.0631	0.0017455	0.0538	0.057375	0.0625	0.004275	-0.0081	-0.003725	0.0026	0.0045705

Device Test: 22.8 LEVEL|SLOPE_2/RSC_B/14/14/0/0/5/200kHz//@SC_RSC_B_200K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

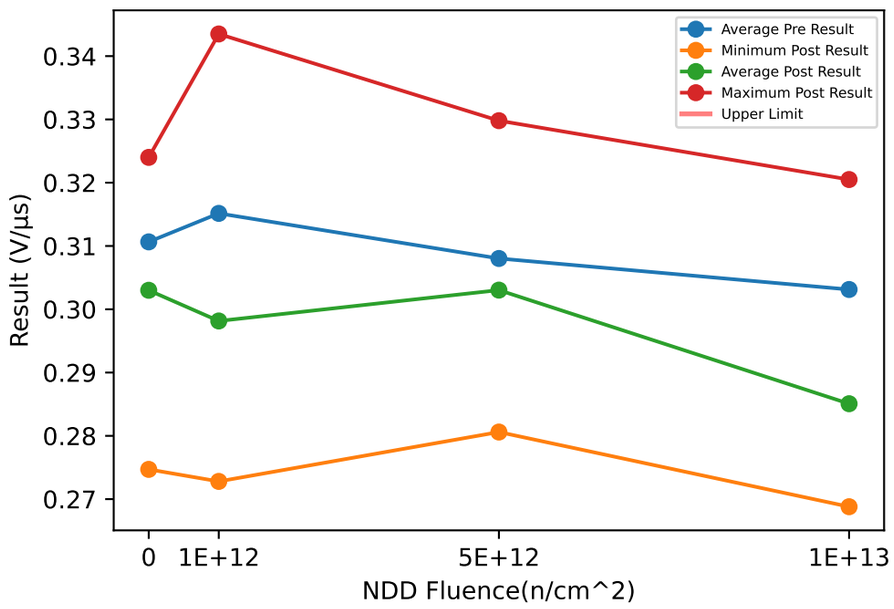
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0665	0.0622	-0.0043
466	1e+12	NDD	0.0624	0.0535	-0.0089
762	0	CORRELATION	0.0638	0.0624	-0.0014
769	1e+12	NDD	0.0639	0.0567	-0.0072
887	1e+12	NDD	0.0674	0.056	-0.0114
891	0	CORRELATION	0.0602	0.0585	-0.0017
927	1e+12	NDD	0.0644	0.0643	-0.0001
967	5e+12	NDD	0.0608	0.0592	-0.0016
1204	1e+13	NDD	0.0593	0.0526	-0.0067
1284	1e+13	NDD	0.0641	0.0503	-0.0138
1292	5e+12	NDD	0.0596	0.0576	-0.002
1364	1e+13	NDD	0.0599	0.0624	0.0025
1383	5e+12	NDD	0.0656	0.061	-0.0046
1388	5e+12	NDD	0.0625	0.061	-0.0015
1427	1e+13	NDD	0.061	0.0547	-0.0063
1666	0	CORRELATION	0.062	0.0544	-0.0076

Test Statistics (V/µs)

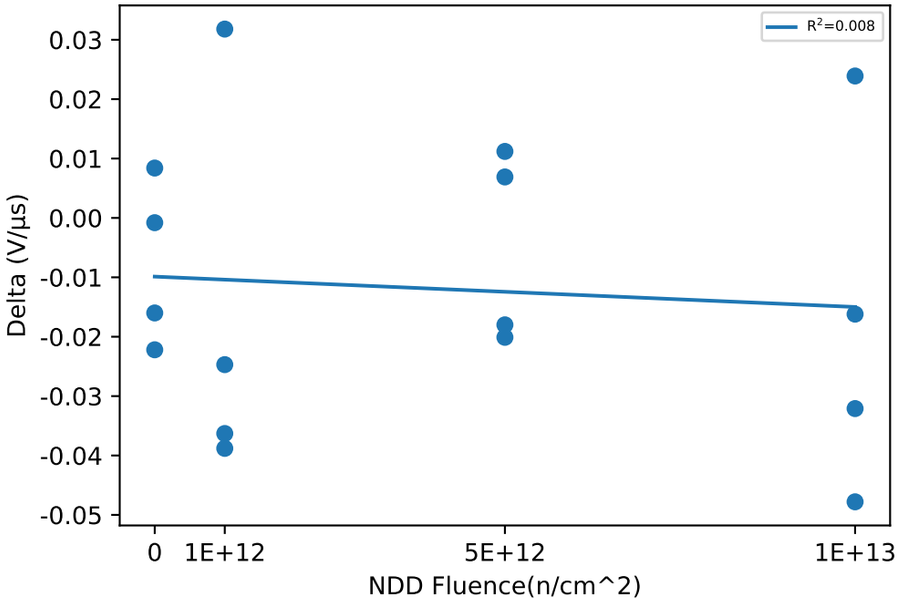
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0602	0.063125	0.0665	0.0026875	0.0544	0.059375	0.0624	0.0037704	-0.0076	-0.00375	-0.0014	0.0028781
1e+12	0.0624	0.064525	0.0674	0.0020966	0.0535	0.057625	0.0643	0.0046572	-0.0114	-0.0069	-0.0001	0.0048504
5e+12	0.0596	0.062125	0.0656	0.0026043	0.0576	0.0597	0.061	0.0016371	-0.0046	-0.002425	-0.0015	0.001466
1e+13	0.0593	0.061075	0.0641	0.002136	0.0503	0.055	0.0624	0.0052504	-0.0138	-0.006075	0.0025	0.0066745

Device Test: 22.9 LEVEL|SLOPE_2/RSC_C/4.5/4.5/0/0/4.5/500kHz//@SC_RSC_C_500K

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (V/µs))

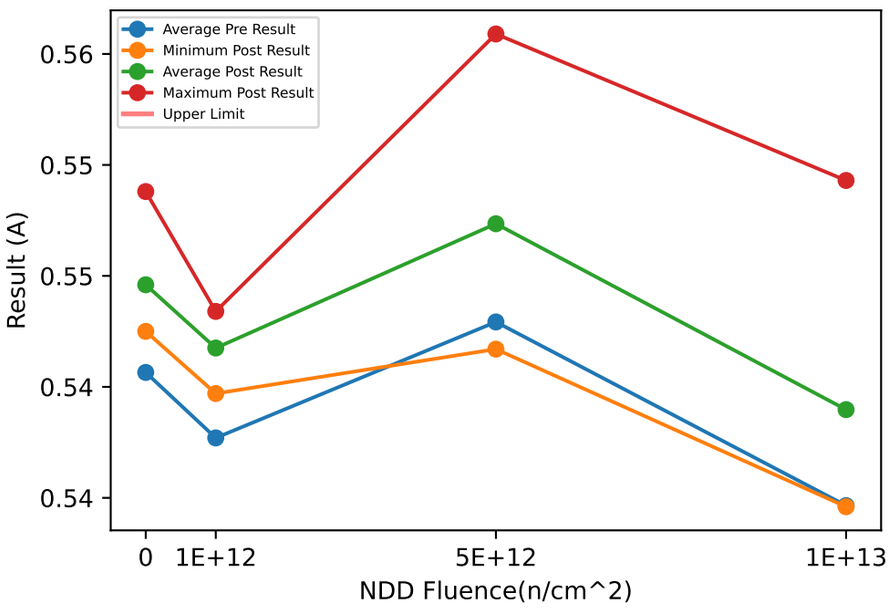
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.3155	0.3239	0.0084
466	1e+12	NDD	0.3116	0.2728	-0.0388
762	0	CORRELATION	0.3248	0.324	-0.0008
769	1e+12	NDD	0.3058	0.2811	-0.0247
887	1e+12	NDD	0.3315	0.2952	-0.0363
891	0	CORRELATION	0.3054	0.2894	-0.016
927	1e+12	NDD	0.3117	0.3435	0.0318
967	5e+12	NDD	0.3007	0.2806	-0.0201
1204	1e+13	NDD	0.2919	0.2757	-0.0162
1284	1e+13	NDD	0.3074	0.2753	-0.0321
1292	5e+12	NDD	0.3013	0.2833	-0.018
1364	1e+13	NDD	0.2966	0.3205	0.0239
1383	5e+12	NDD	0.3186	0.3298	0.0112
1388	5e+12	NDD	0.3115	0.3184	0.0069
1427	1e+13	NDD	0.3166	0.2688	-0.0478
1666	0	CORRELATION	0.2969	0.2747	-0.0222

Test Statistics (V/µs)

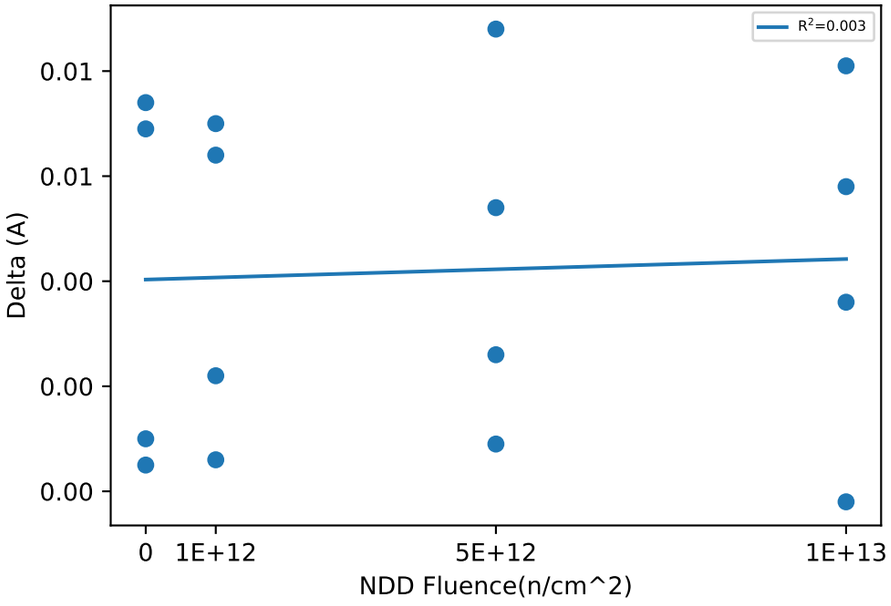
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.2969	0.31065	0.3248	0.012116	0.2747	0.303	0.324	0.024924	-0.0222	-0.00765	0.0084	0.013976
1e+12	0.3058	0.31515	0.3315	0.011244	0.2728	0.29815	0.3435	0.031616	-0.0388	-0.017	0.0318	0.033108
5e+12	0.3007	0.30802	0.3186	0.0086176	0.2806	0.30302	0.3298	0.024801	-0.0201	-0.005	0.0112	0.016341
1e+13	0.2919	0.30312	0.3166	0.011082	0.2688	0.28507	0.3205	0.023827	-0.0478	-0.01805	0.0239	0.030799

Device Test: 23.1 CURRENT|SOURCE/OUTH/4.5/4.5/0/0/4.5/500kHz//@OUT_IOH_4P5V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (A))

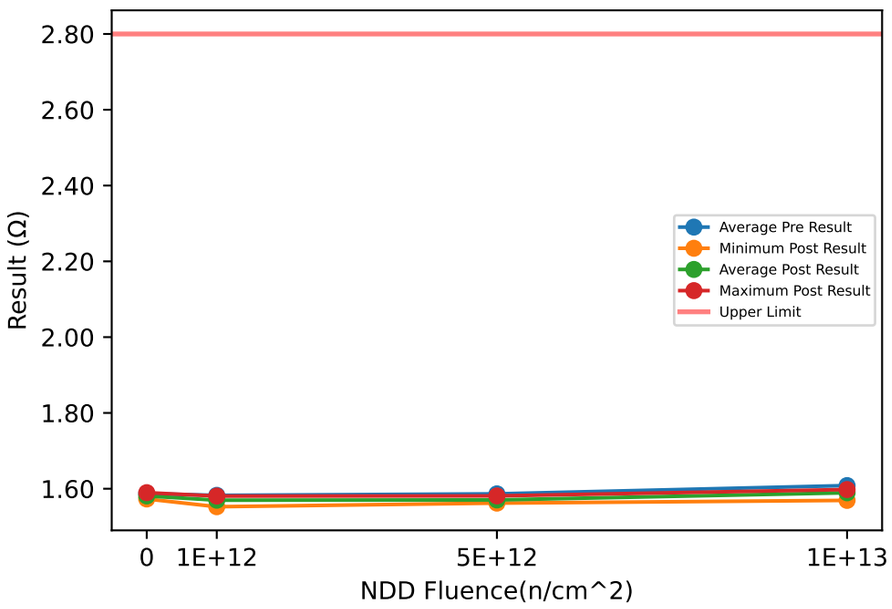
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.5483	0.5488	0.0005
466	1e+12	NDD	0.5404	0.541	0.0006
762	0	CORRELATION	0.536	0.5429	0.0069
769	1e+12	NDD	0.5412	0.5434	0.0022
887	1e+12	NDD	0.5333	0.5397	0.0064
891	0	CORRELATION	0.5351	0.5425	0.0074
927	1e+12	NDD	0.5359	0.5429	0.007
967	5e+12	NDD	0.5408	0.5434	0.0026
1204	1e+13	NDD	0.5316	0.5374	0.0058
1284	1e+13	NDD	0.5348	0.5346	-0.0002
1292	5e+12	NDD	0.5363	0.5417	0.0054
1364	1e+13	NDD	0.531	0.5346	0.0036
1383	5e+12	NDD	0.5396	0.5484	0.0088
1388	5e+12	NDD	0.555	0.5559	0.0009
1427	1e+13	NDD	0.5412	0.5493	0.0081
1666	0	CORRELATION	0.5432	0.5442	0.001

Test Statistics (A)

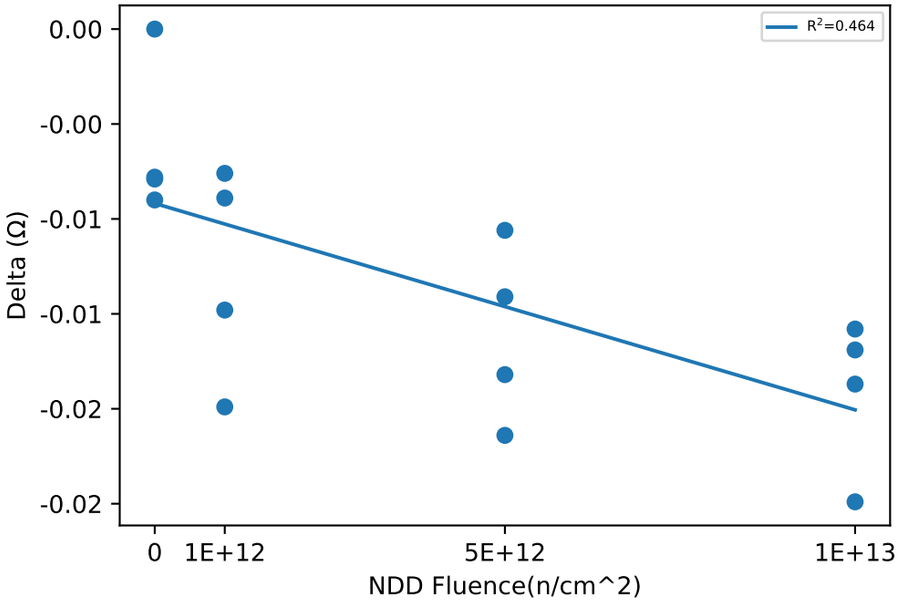
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.5351	0.54065	0.5483	0.006257	0.5425	0.5446	0.5488	0.0028925	0.0005	0.00395	0.0074	0.0037063
1e+12	0.5333	0.5377	0.5412	0.0037479	0.5397	0.54175	0.5434	0.0017137	0.0006	0.00405	0.007	0.0031385
5e+12	0.5363	0.54292	0.555	0.0082718	0.5417	0.54735	0.5559	0.00637	0.0009	0.004425	0.0088	0.0034568
1e+13	0.531	0.53465	0.5412	0.0046744	0.5346	0.53897	0.5493	0.0070087	-0.0002	0.004325	0.0081	0.0035321

Device Test: 23.10 LEVEL|LS_RDSON/OUTL/12/12/100/0/5/500kHz//@ROL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 2.8 (Ω))

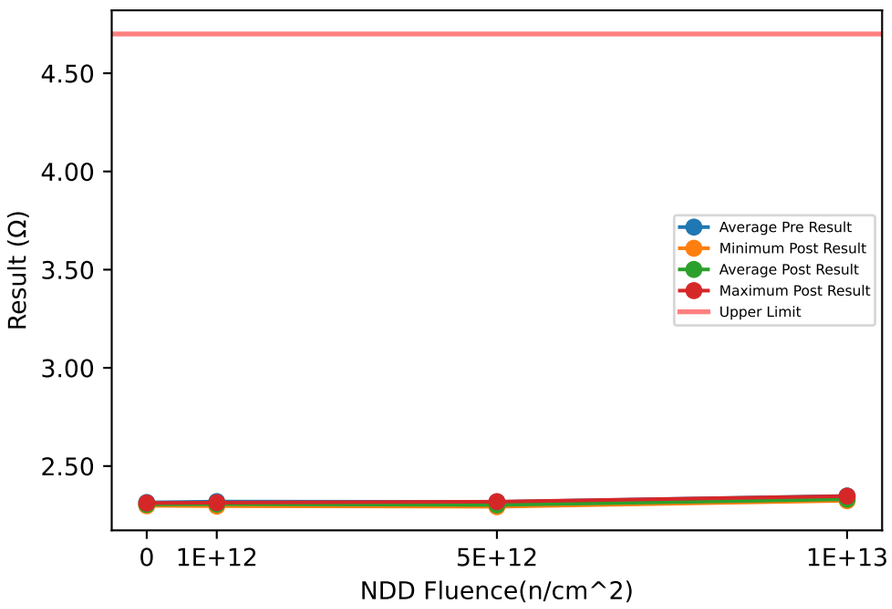
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.5986	1.5896	-0.009
466	1e+12	NDD	1.5724	1.5525	-0.0199
762	0	CORRELATION	1.5914	1.5835	-0.0079
769	1e+12	NDD	1.5895	1.5806	-0.0089
887	1e+12	NDD	1.5843	1.5695	-0.0148
891	0	CORRELATION	1.5776	1.5776	0
927	1e+12	NDD	1.5838	1.5762	-0.0076
967	5e+12	NDD	1.5851	1.571	-0.0141
1204	1e+13	NDD	1.6165	1.5978	-0.0187
1284	1e+13	NDD	1.6192	1.5943	-0.0249
1292	5e+12	NDD	1.6024	1.581	-0.0214
1364	1e+13	NDD	1.6115	1.5957	-0.0158
1383	5e+12	NDD	1.5781	1.5675	-0.0106
1388	5e+12	NDD	1.5802	1.562	-0.0182
1427	1e+13	NDD	1.5861	1.5692	-0.0169
1666	0	CORRELATION	1.5807	1.5729	-0.0078

Test Statistics (Ω)

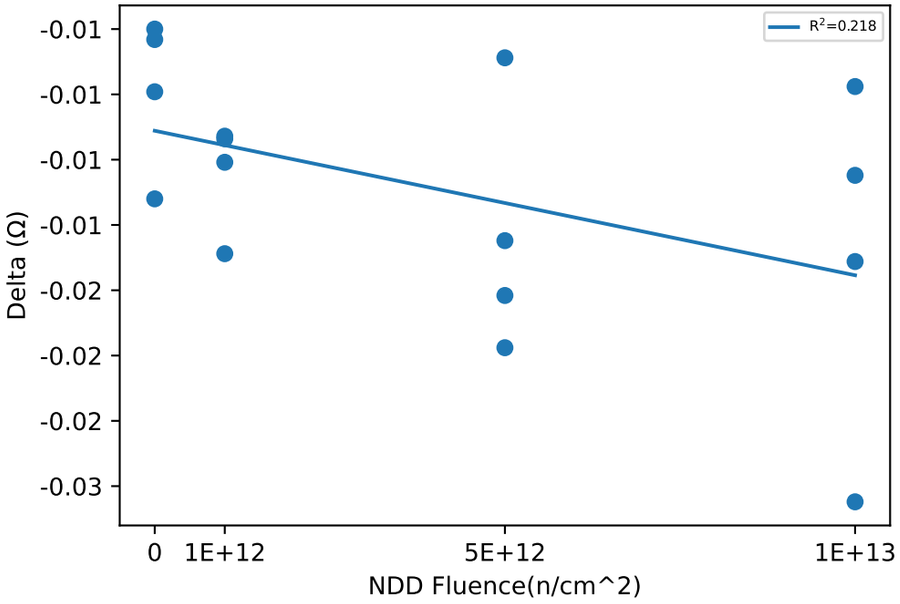
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5776	1.5871	1.5986	0.0096945	1.5729	1.5809	1.5896	0.007242	-0.009	-0.006175	0	0.0041524
1e+12	1.5724	1.5825	1.5895	0.0072097	1.5525	1.5697	1.5806	0.012342	-0.0199	-0.0128	-0.0076	0.0056763
5e+12	1.5781	1.5865	1.6024	0.01103	1.562	1.5704	1.581	0.0079935	-0.0214	-0.016075	-0.0106	0.0047169
1e+13	1.5861	1.6083	1.6192	0.015156	1.5692	1.5893	1.5978	0.013444	-0.0249	-0.019075	-0.0158	0.0040631

Device Test: 23.11 LEVEL|HS_RDSON/OUTH/14/14/100/0/5/500kHz//@ROH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 4.7 (Ω))

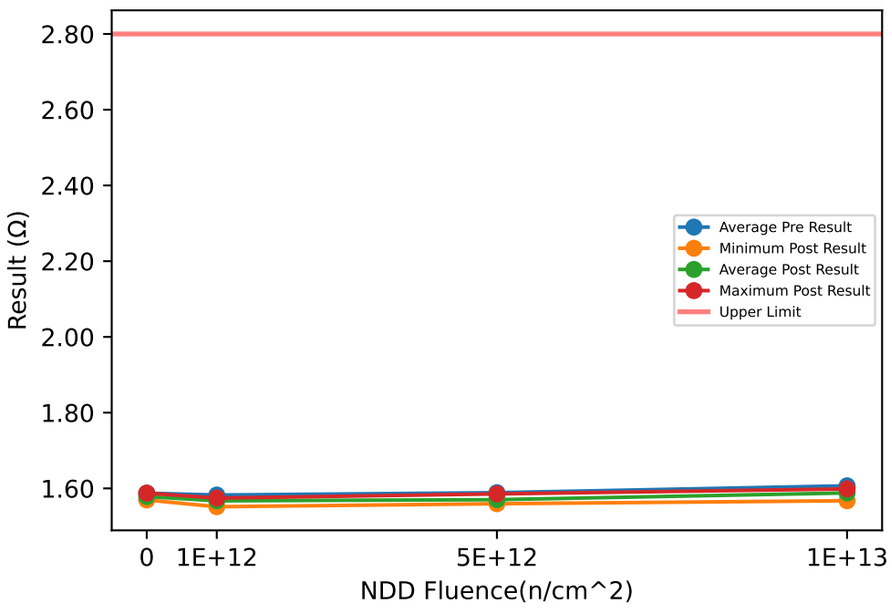
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.3054	2.2979	-0.0075
466	1e+12	NDD	2.3185	2.3059	-0.0126
762	0	CORRELATION	2.3126	2.3047	-0.0079
769	1e+12	NDD	2.3076	2.296	-0.0116
887	1e+12	NDD	2.3249	2.3088	-0.0161
891	0	CORRELATION	2.3183	2.3043	-0.014
927	1e+12	NDD	2.3255	2.3138	-0.0117
967	5e+12	NDD	2.3199	2.3022	-0.0177
1204	1e+13	NDD	2.3431	2.33	-0.0131
1284	1e+13	NDD	2.3566	2.3469	-0.0097
1292	5e+12	NDD	2.3342	2.3186	-0.0156
1364	1e+13	NDD	2.3399	2.3235	-0.0164
1383	5e+12	NDD	2.3127	2.293	-0.0197
1388	5e+12	NDD	2.3033	2.2947	-0.0086
1427	1e+13	NDD	2.351	2.3254	-0.0256
1666	0	CORRELATION	2.3217	2.3118	-0.0099

Test Statistics (Ω)

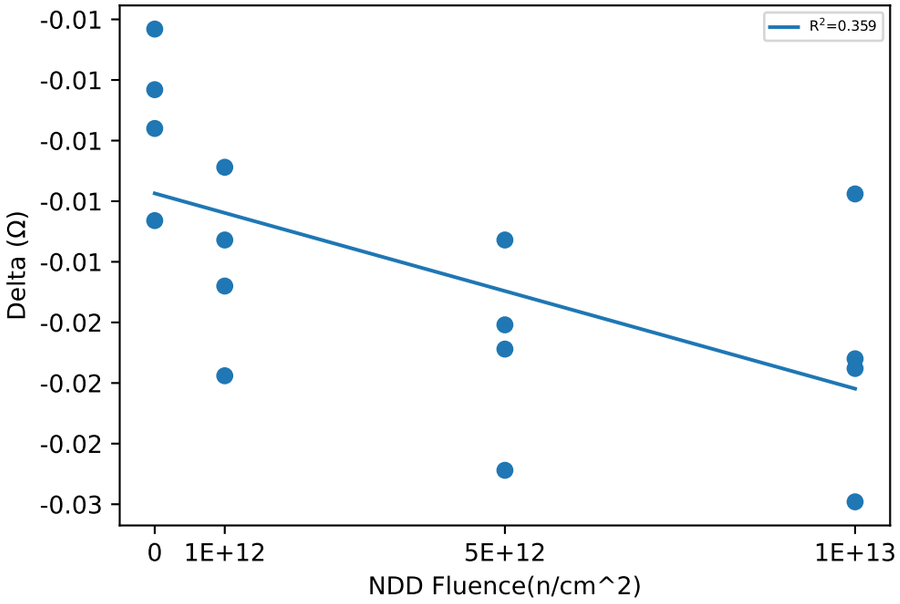
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3054	2.3145	2.3217	0.0071344	2.2979	2.3047	2.3118	0.0056806	-0.014	-0.009825	-0.0075	0.0029748
1e+12	2.3076	2.3191	2.3255	0.0083108	2.296	2.3061	2.3138	0.0074973	-0.0161	-0.013	-0.0116	0.002115
5e+12	2.3033	2.3175	2.3342	0.01303	2.293	2.3021	2.3186	0.011688	-0.0197	-0.0154	-0.0086	0.0048325
1e+13	2.3399	2.3476	2.3566	0.0075739	2.3235	2.3315	2.3469	0.010655	-0.0256	-0.0162	-0.0097	0.0068376

Device Test: 23.12 LEVEL|LS_RDSON/OUTL/14/14/100/0/5/500kHz//@ROL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 2.8 (Ω))

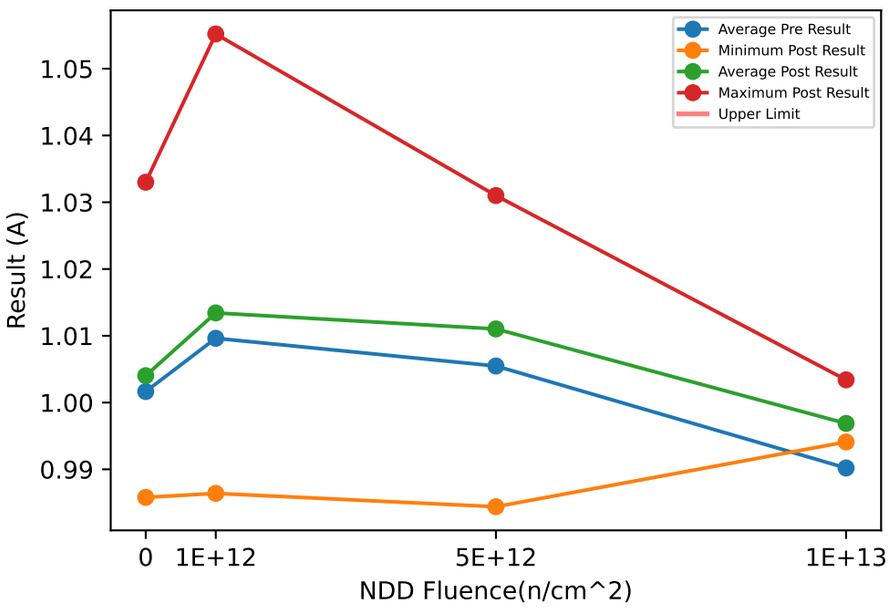
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.597	1.5875	-0.0095
466	1e+12	NDD	1.5713	1.5516	-0.0197
762	0	CORRELATION	1.5949	1.5816	-0.0133
769	1e+12	NDD	1.5904	1.5744	-0.016
887	1e+12	NDD	1.5835	1.5694	-0.0141
891	0	CORRELATION	1.5803	1.5749	-0.0054
927	1e+12	NDD	1.5846	1.5735	-0.0111
967	5e+12	NDD	1.5896	1.572	-0.0176
1204	1e+13	NDD	1.6141	1.5951	-0.019
1284	1e+13	NDD	1.6157	1.5908	-0.0249
1292	5e+12	NDD	1.604	1.5854	-0.0186
1364	1e+13	NDD	1.6107	1.5985	-0.0122
1383	5e+12	NDD	1.5779	1.5638	-0.0141
1388	5e+12	NDD	1.5831	1.5595	-0.0236
1427	1e+13	NDD	1.5868	1.5674	-0.0194
1666	0	CORRELATION	1.5773	1.5694	-0.0079

Test Statistics (Ω)

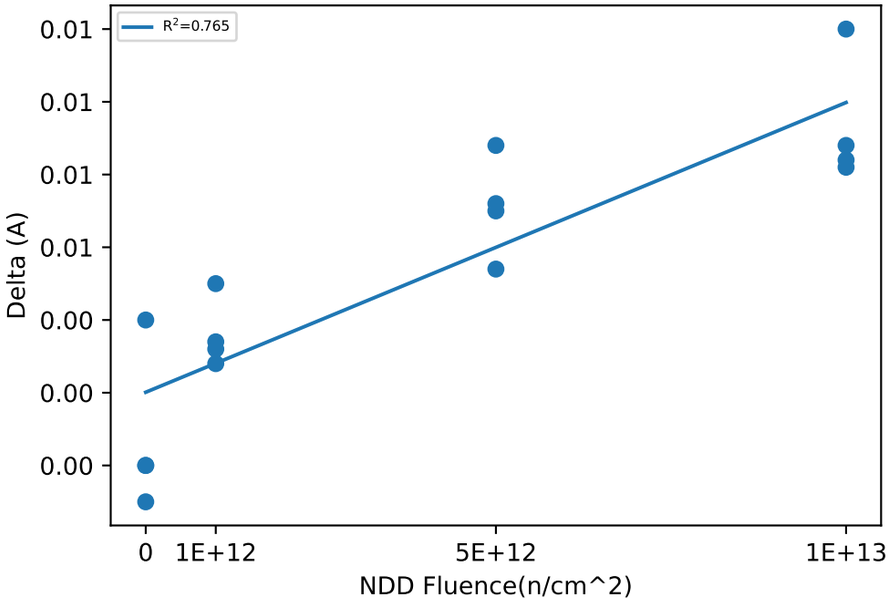
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5773	1.5874	1.597	0.010014	1.5694	1.5783	1.5875	0.0078801	-0.0133	-0.009025	-0.0054	0.003312
1e+12	1.5713	1.5824	1.5904	0.008026	1.5516	1.5672	1.5744	0.010642	-0.0197	-0.015225	-0.0111	0.0036013
5e+12	1.5779	1.5886	1.604	0.011297	1.5595	1.5702	1.5854	0.011398	-0.0236	-0.018475	-0.0141	0.0039238
1e+13	1.5868	1.6068	1.6157	0.013512	1.5674	1.5879	1.5985	0.014058	-0.0249	-0.018875	-0.0122	0.0052009

Device Test: 23.2 CURRENT|SINK/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_IOL_4P5V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (A))

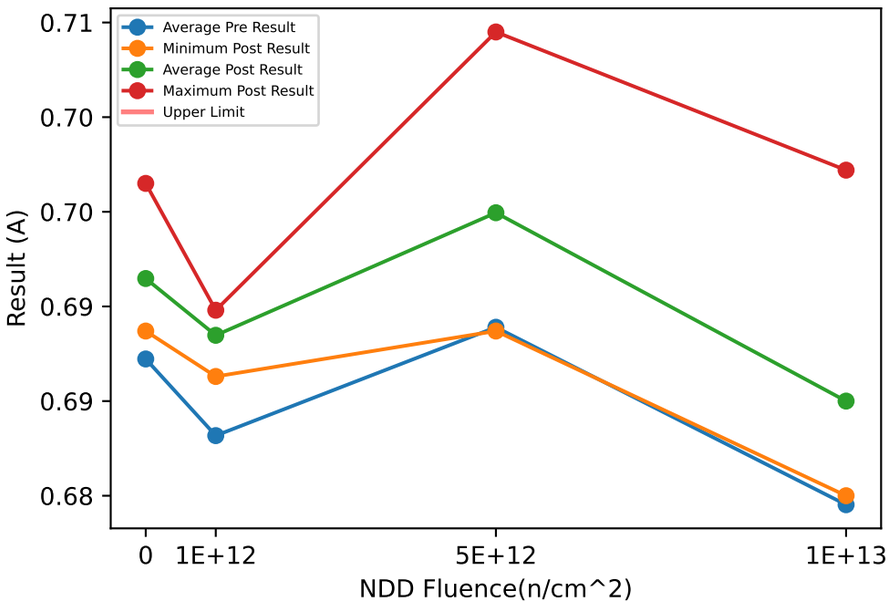
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9848	0.9868	0.002
466	1e+12	NDD	1.0516	1.0552	0.0036
762	0	CORRELATION	1.0085	1.0105	0.002
769	1e+12	NDD	0.9989	1.0034	0.0045
887	1e+12	NDD	1.0053	1.0087	0.0034
891	0	CORRELATION	0.9843	0.9858	0.0015
927	1e+12	NDD	0.9827	0.9864	0.0037
967	5e+12	NDD	0.978	0.9844	0.0064
1204	1e+13	NDD	0.9879	0.9941	0.0062
1284	1e+13	NDD	0.9884	0.9945	0.0061
1292	5e+12	NDD	0.9989	1.0036	0.0047
1364	1e+13	NDD	0.9875	0.9955	0.008
1383	5e+12	NDD	1.0254	1.031	0.0056
1388	5e+12	NDD	1.0196	1.0251	0.0055
1427	1e+13	NDD	0.997	1.0034	0.0064
1666	0	CORRELATION	1.029	1.033	0.004

Test Statistics (A)

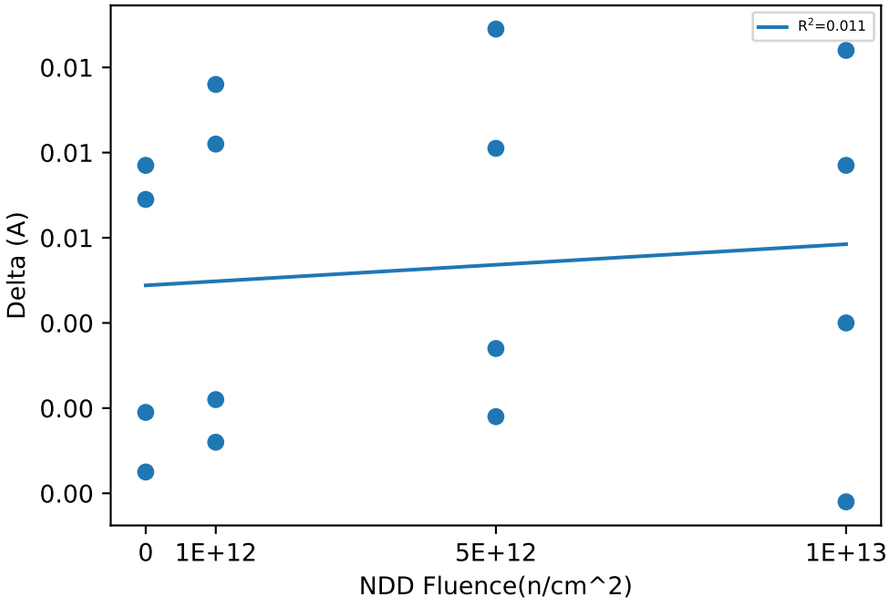
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9843	1.0016	1.029	0.021447	0.9858	1.004	1.033	0.022438	0.0015	0.002375	0.004	0.0011087
1e+12	0.9827	1.0096	1.0516	0.029556	0.9864	1.0134	1.0552	0.02943	0.0034	0.0038	0.0045	0.00048305
5e+12	0.978	1.0055	1.0254	0.021561	0.9844	1.011	1.031	0.0213	0.0047	0.00555	0.0064	0.00069522
1e+13	0.9875	0.9902	0.997	0.0045483	0.9941	0.99688	1.0034	0.0043897	0.0061	0.006675	0.008	0.00089209

Device Test: 23.3 CURRENT|SOURCE/OUTH/5/5/0/0/5/500kHz//@OUT_IOH_5V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (A))

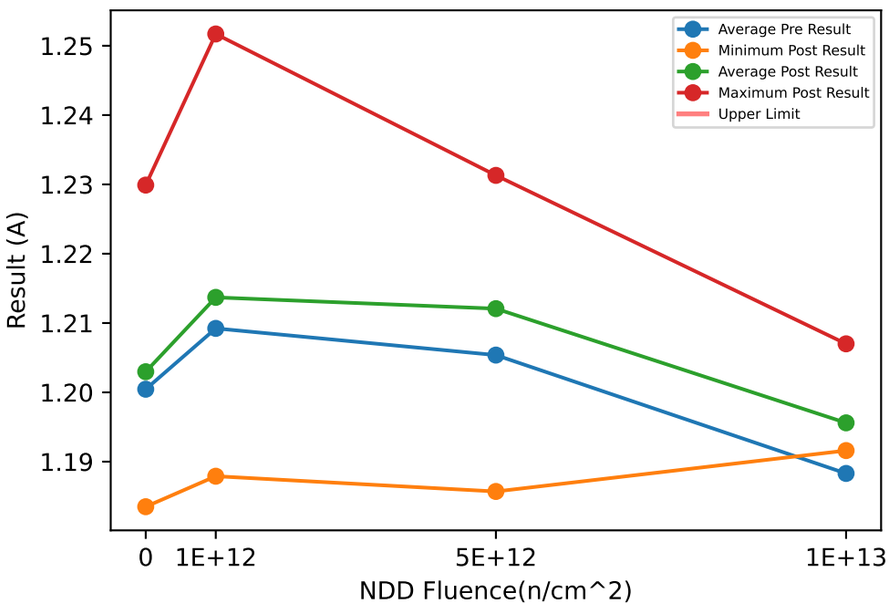
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.696	0.6965	0.0005
466	1e+12	NDD	0.6869	0.6881	0.0012
762	0	CORRELATION	0.6825	0.6894	0.0069
769	1e+12	NDD	0.6875	0.6897	0.0022
887	1e+12	NDD	0.6781	0.6863	0.0082
891	0	CORRELATION	0.681	0.6887	0.0077
927	1e+12	NDD	0.6802	0.6898	0.0096
967	5e+12	NDD	0.6867	0.6901	0.0034
1204	1e+13	NDD	0.6751	0.6828	0.0077
1284	1e+13	NDD	0.6802	0.68	-0.0002
1292	5e+12	NDD	0.6806	0.6887	0.0081
1364	1e+13	NDD	0.676	0.68	0.004
1383	5e+12	NDD	0.6856	0.6965	0.0109
1388	5e+12	NDD	0.7027	0.7045	0.0018
1427	1e+13	NDD	0.6868	0.6972	0.0104
1666	0	CORRELATION	0.6894	0.6913	0.0019

Test Statistics (A)

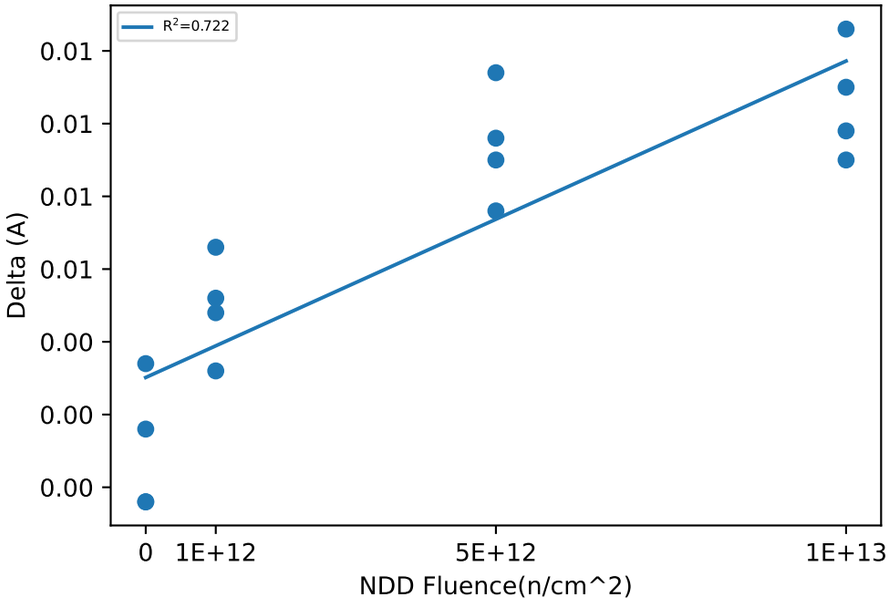
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.681	0.68722	0.696	0.0068995	0.6887	0.69148	0.6965	0.0035255	0.0005	0.00425	0.0077	0.0035828
1e+12	0.6781	0.68317	0.6875	0.0047324	0.6863	0.68847	0.6898	0.001646	0.0012	0.0053	0.0096	0.0042158
5e+12	0.6806	0.6889	0.7027	0.0095753	0.6887	0.69495	0.7045	0.0072155	0.0018	0.00605	0.0109	0.0041956
1e+13	0.6751	0.67953	0.6868	0.005335	0.68	0.685	0.6972	0.0082397	-0.0002	0.005475	0.0104	0.0046039

Device Test: 23.4 CURRENT|SINK/OUTL/5/5/0/0/5/500kHz//@OUT_IOL_5V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (No Limits Specified (A))

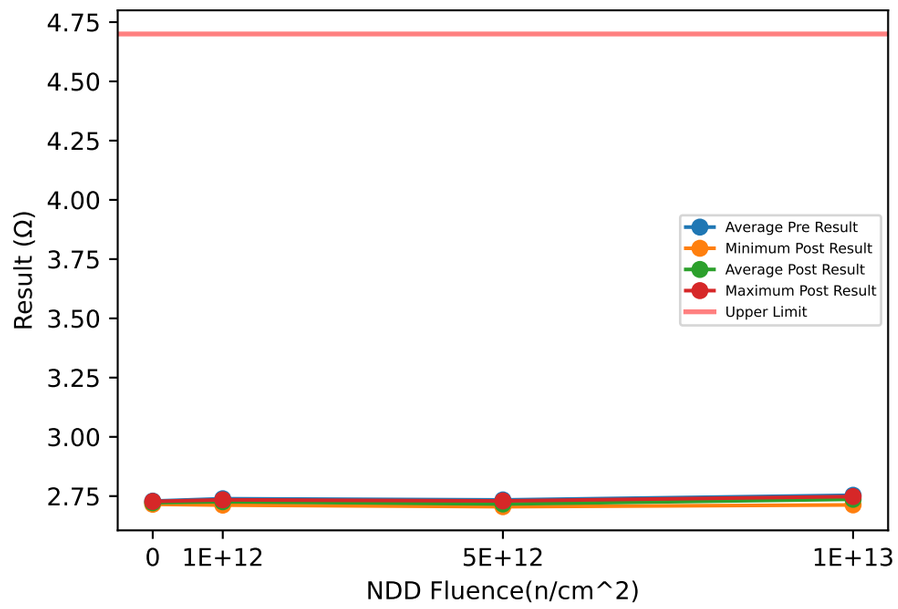
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.1807	1.1835	0.0028
466	1e+12	NDD	1.2471	1.2517	0.0046
762	0	CORRELATION	1.2066	1.2084	0.0018
769	1e+12	NDD	1.2009	1.2062	0.0053
887	1e+12	NDD	1.2054	1.209	0.0036
891	0	CORRELATION	1.1883	1.1901	0.0018
927	1e+12	NDD	1.1835	1.1879	0.0044
967	5e+12	NDD	1.178	1.1857	0.0077
1204	1e+13	NDD	1.1851	1.192	0.0069
1284	1e+13	NDD	1.1851	1.1916	0.0065
1292	5e+12	NDD	1.1989	1.2047	0.0058
1364	1e+13	NDD	1.1835	1.1918	0.0083
1383	5e+12	NDD	1.2248	1.2313	0.0065
1388	5e+12	NDD	1.2198	1.2266	0.0068
1427	1e+13	NDD	1.1995	1.207	0.0075
1666	0	CORRELATION	1.2262	1.2299	0.0037

Test Statistics (A)

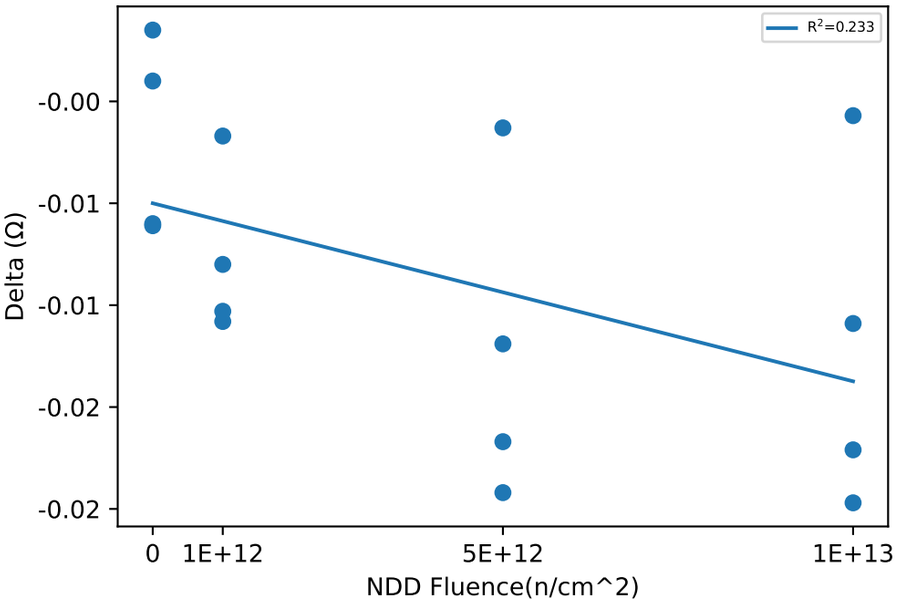
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.1807	1.2005	1.2262	0.020319	1.1835	1.203	1.2299	0.020812	0.0018	0.002525	0.0037	0.00091424
1e+12	1.1835	1.2092	1.2471	0.026958	1.1879	1.2137	1.2517	0.027006	0.0036	0.004475	0.0053	0.0006994
5e+12	1.178	1.2054	1.2248	0.021422	1.1857	1.2121	1.2313	0.02106	0.0058	0.0067	0.0077	0.0007874
1e+13	1.1835	1.1883	1.1995	0.0075047	1.1916	1.1956	1.207	0.0076018	0.0065	0.0073	0.0083	0.00078316

Device Test: 23.5 LEVEL|HS_RDSON/OUTH/4.5/4.5/100/0/4.5/500kHz//@ROH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 4.7 (Ω))

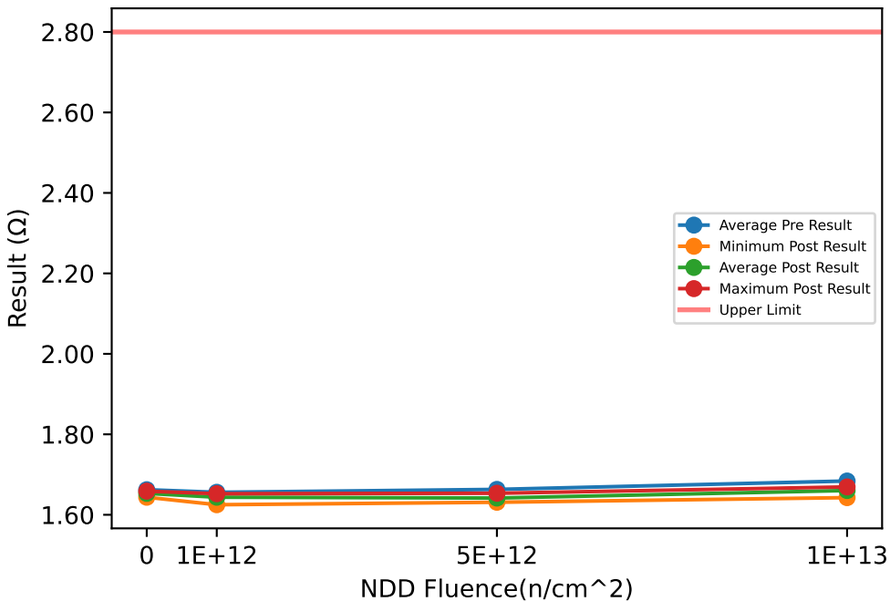
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.717	2.7155	-0.0015
466	1e+12	NDD	2.7364	2.7297	-0.0067
762	0	CORRELATION	2.7326	2.7215	-0.0111
769	1e+12	NDD	2.7277	2.7119	-0.0158
887	1e+12	NDD	2.7473	2.7343	-0.013
891	0	CORRELATION	2.735	2.724	-0.011
927	1e+12	NDD	2.7442	2.7289	-0.0153
967	5e+12	NDD	2.7463	2.7246	-0.0217
1204	1e+13	NDD	2.7594	2.7373	-0.0221
1284	1e+13	NDD	2.7538	2.7481	-0.0057
1292	5e+12	NDD	2.7465	2.7296	-0.0169
1364	1e+13	NDD	2.7635	2.7476	-0.0159
1383	5e+12	NDD	2.7313	2.7071	-0.0242
1388	5e+12	NDD	2.7115	2.7052	-0.0063
1427	1e+13	NDD	2.7375	2.7128	-0.0247
1666	0	CORRELATION	2.7314	2.7274	-0.004

Test Statistics (Ω)

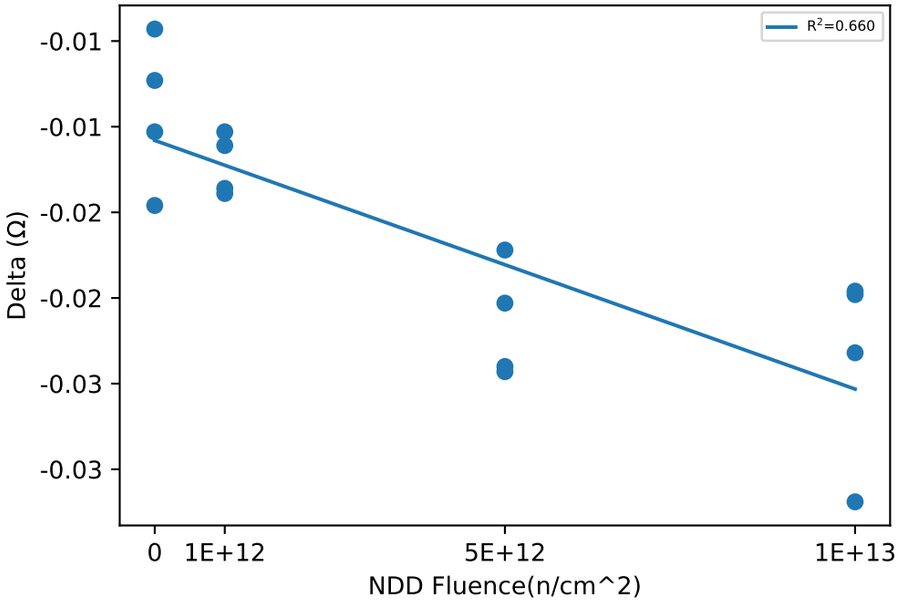
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.717	2.729	2.735	0.0081388	2.7155	2.7221	2.7274	0.0050206	-0.0111	-0.0069	-0.0015	0.0048997
1e+12	2.7277	2.7389	2.7473	0.0087624	2.7119	2.7262	2.7343	0.0098258	-0.0158	-0.0127	-0.0067	0.0041817
5e+12	2.7115	2.7339	2.7465	0.016543	2.7052	2.7166	2.7296	0.012291	-0.0242	-0.017275	-0.0063	0.0079189
1e+13	2.7375	2.7535	2.7635	0.011415	2.7128	2.7365	2.7481	0.016534	-0.0247	-0.0171	-0.0057	0.0084491

Device Test: 23.6 LEVEL|LS_RDSON/OUTL/4.5/4.5/100/0/4.5/500kHz//@ROL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 2.8 (Ω))

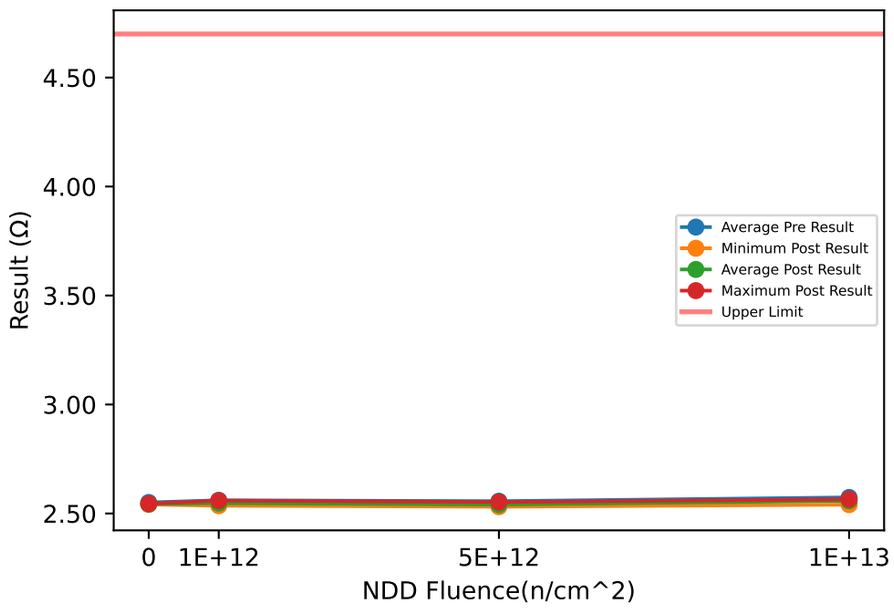
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.6732	1.6586	-0.0146
466	1e+12	NDD	1.6386	1.625	-0.0136
762	0	CORRELATION	1.666	1.6587	-0.0073
769	1e+12	NDD	1.6655	1.6516	-0.0139
887	1e+12	NDD	1.6568	1.6457	-0.0111
891	0	CORRELATION	1.6561	1.6518	-0.0043
927	1e+12	NDD	1.6626	1.6523	-0.0103
967	5e+12	NDD	1.6675	1.6472	-0.0203
1204	1e+13	NDD	1.6892	1.666	-0.0232
1284	1e+13	NDD	1.6953	1.6634	-0.0319
1292	5e+12	NDD	1.6775	1.6535	-0.024
1364	1e+13	NDD	1.6888	1.6692	-0.0196
1383	5e+12	NDD	1.6518	1.6346	-0.0172
1388	5e+12	NDD	1.6554	1.6311	-0.0243
1427	1e+13	NDD	1.6624	1.6426	-0.0198
1666	0	CORRELATION	1.6539	1.6436	-0.0103

Test Statistics (Ω)

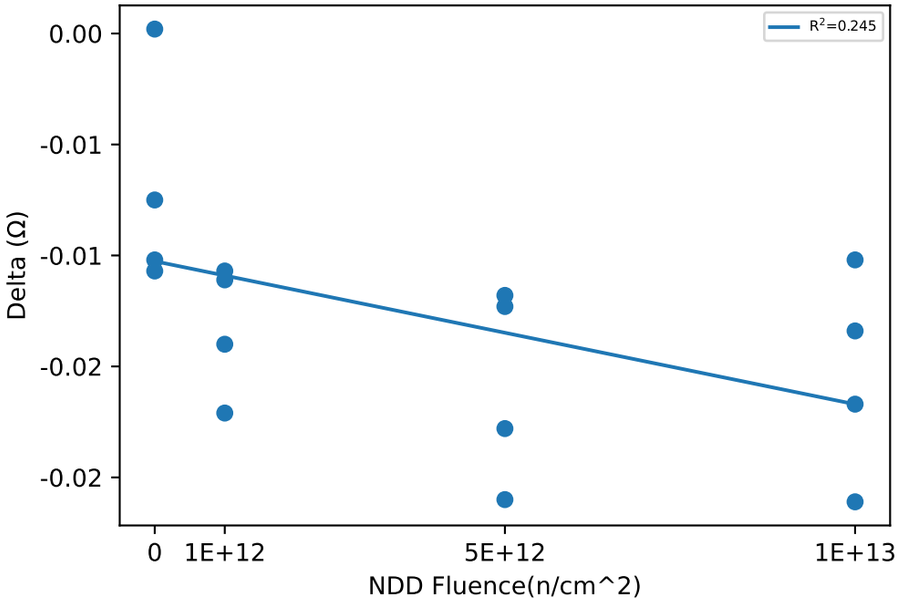
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.6539	1.6623	1.6732	0.0089722	1.6436	1.6532	1.6587	0.0071537	-0.0146	-0.009125	-0.0043	0.0043957
1e+12	1.6386	1.6559	1.6655	0.012071	1.625	1.6437	1.6523	0.012781	-0.0139	-0.012225	-0.0103	0.0017951
5e+12	1.6518	1.663	1.6775	0.011743	1.6311	1.6416	1.6535	0.010523	-0.0243	-0.02145	-0.0172	0.003367
1e+13	1.6624	1.6839	1.6953	0.014655	1.6426	1.6603	1.6692	0.012036	-0.0319	-0.023625	-0.0196	0.0057587

Device Test: 23.7 LEVEL|HS_RDSON/OUTH/5/5/100/0/5/500kHz//@ROH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 4.7 (Ω))

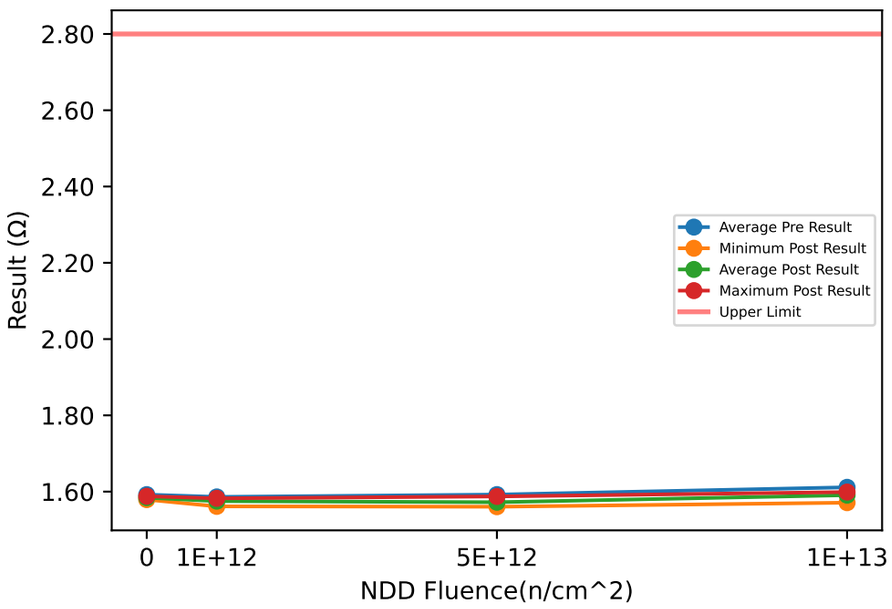
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.5412	2.5414	0.0002
466	1e+12	NDD	2.5558	2.5447	-0.0111
762	0	CORRELATION	2.5533	2.5431	-0.0102
769	1e+12	NDD	2.5496	2.5356	-0.014
887	1e+12	NDD	2.5695	2.5588	-0.0107
891	0	CORRELATION	2.5515	2.544	-0.0075
927	1e+12	NDD	2.567	2.5499	-0.0171
967	5e+12	NDD	2.5639	2.5461	-0.0178
1204	1e+13	NDD	2.5758	2.5624	-0.0134
1284	1e+13	NDD	2.5754	2.5652	-0.0102
1292	5e+12	NDD	2.5647	2.5524	-0.0123
1364	1e+13	NDD	2.5816	2.5649	-0.0167
1383	5e+12	NDD	2.554	2.533	-0.021
1388	5e+12	NDD	2.5428	2.531	-0.0118
1427	1e+13	NDD	2.5615	2.5404	-0.0211
1666	0	CORRELATION	2.5556	2.5449	-0.0107

Test Statistics (Ω)

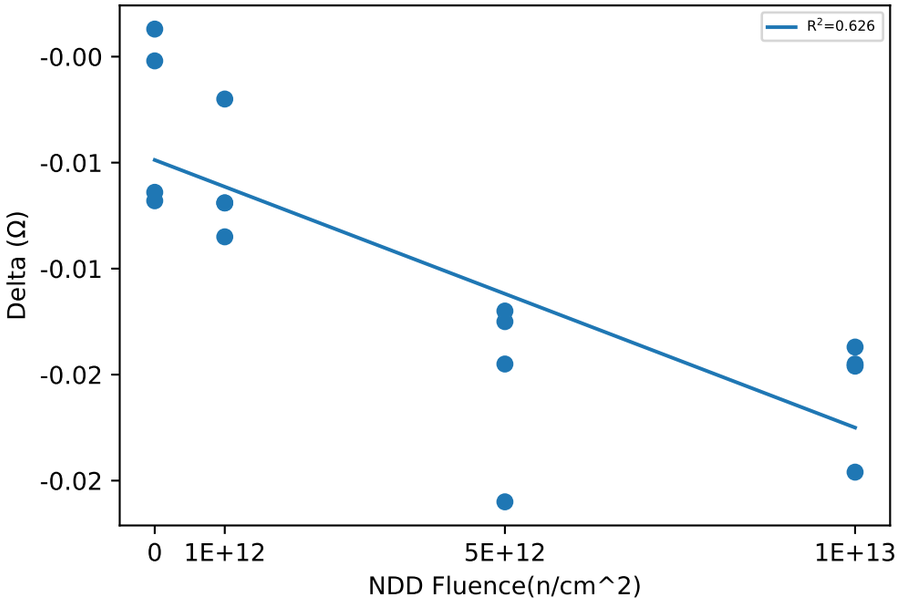
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.5412	2.5504	2.5556	0.0063587	2.5414	2.5434	2.5449	0.0014933	-0.0107	-0.00705	0.0002	0.0050336
1e+12	2.5496	2.5605	2.5695	0.0093835	2.5356	2.5473	2.5588	0.0097065	-0.0171	-0.013225	-0.0107	0.0029725
5e+12	2.5428	2.5564	2.5647	0.010261	2.531	2.5406	2.5524	0.010318	-0.021	-0.015725	-0.0118	0.0044448
1e+13	2.5615	2.5736	2.5816	0.008534	2.5404	2.5582	2.5652	0.011949	-0.0211	-0.01535	-0.0102	0.0046623

Device Test: 23.8 LEVEL|LS_RDSON/OUTL/5/5/100/0/5/500kHz//@ROL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 2.8 (Ω))

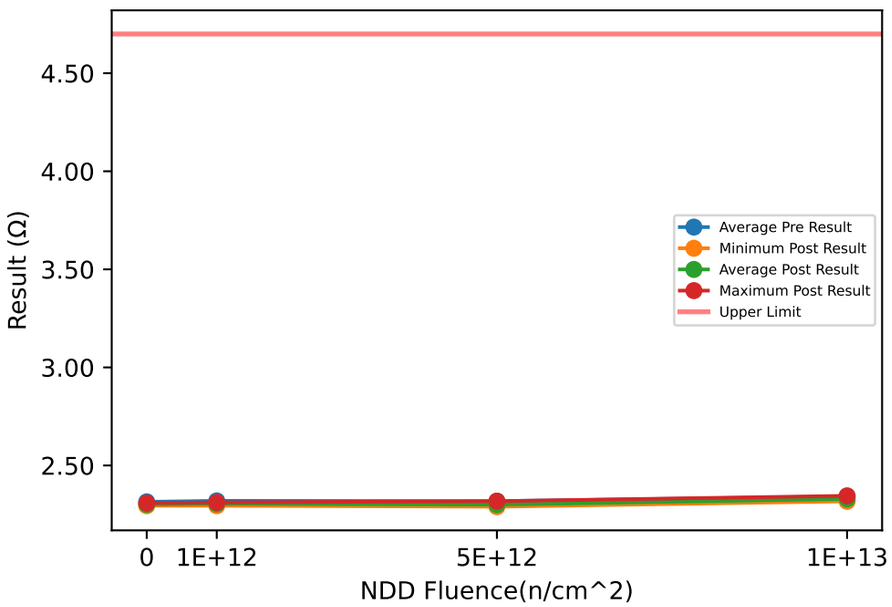
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.5996	1.5878	-0.0118
466	1e+12	NDD	1.5748	1.5613	-0.0135
762	0	CORRELATION	1.5983	1.5869	-0.0114
769	1e+12	NDD	1.5894	1.5824	-0.007
887	1e+12	NDD	1.5877	1.5758	-0.0119
891	0	CORRELATION	1.5865	1.5828	-0.0037
927	1e+12	NDD	1.5926	1.5807	-0.0119
967	5e+12	NDD	1.593	1.5755	-0.0175
1204	1e+13	NDD	1.6184	1.5988	-0.0196
1284	1e+13	NDD	1.6217	1.5971	-0.0246
1292	5e+12	NDD	1.6068	1.5873	-0.0195
1364	1e+13	NDD	1.6153	1.5958	-0.0195
1383	5e+12	NDD	1.5826	1.5656	-0.017
1388	5e+12	NDD	1.5864	1.5604	-0.026
1427	1e+13	NDD	1.5897	1.571	-0.0187
1666	0	CORRELATION	1.5842	1.579	-0.0052

Test Statistics (Ω)

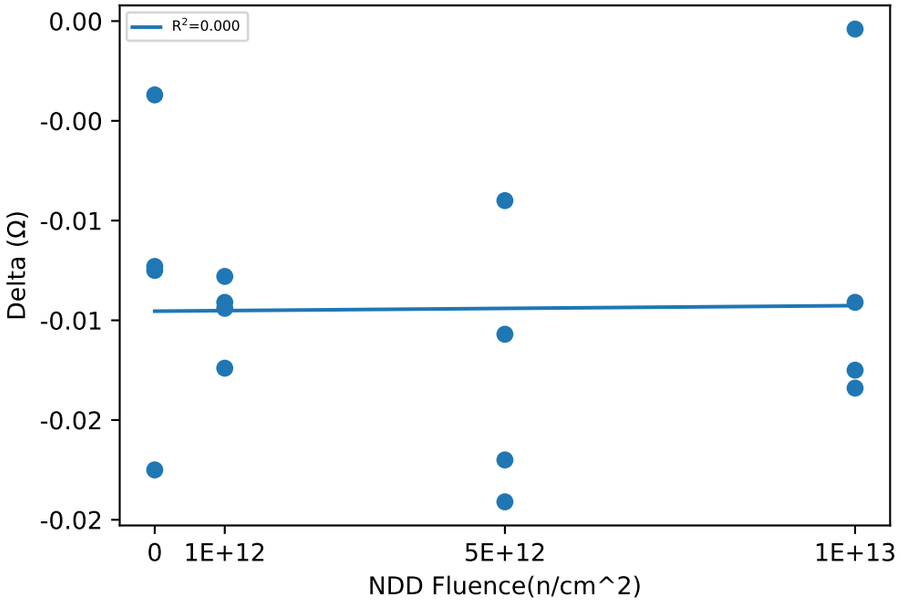
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.5842	1.5921	1.5996	0.0079257	1.579	1.5841	1.5878	0.0040508	-0.0118	-0.008025	-0.0037	0.0041764
1e+12	1.5748	1.5861	1.5926	0.0078185	1.5613	1.5751	1.5824	0.0095842	-0.0135	-0.011075	-0.007	0.0028194
5e+12	1.5826	1.5922	1.6068	0.01064	1.5604	1.5722	1.5873	0.011856	-0.026	-0.02	-0.017	0.0041433
1e+13	1.5897	1.6113	1.6217	0.014619	1.571	1.5907	1.5988	0.013174	-0.0246	-0.0206	-0.0187	0.0026969

Device Test: 23.9 LEVEL|HS_RDSON/OUTH/12/12/100/0/5/500kHz//@ROH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



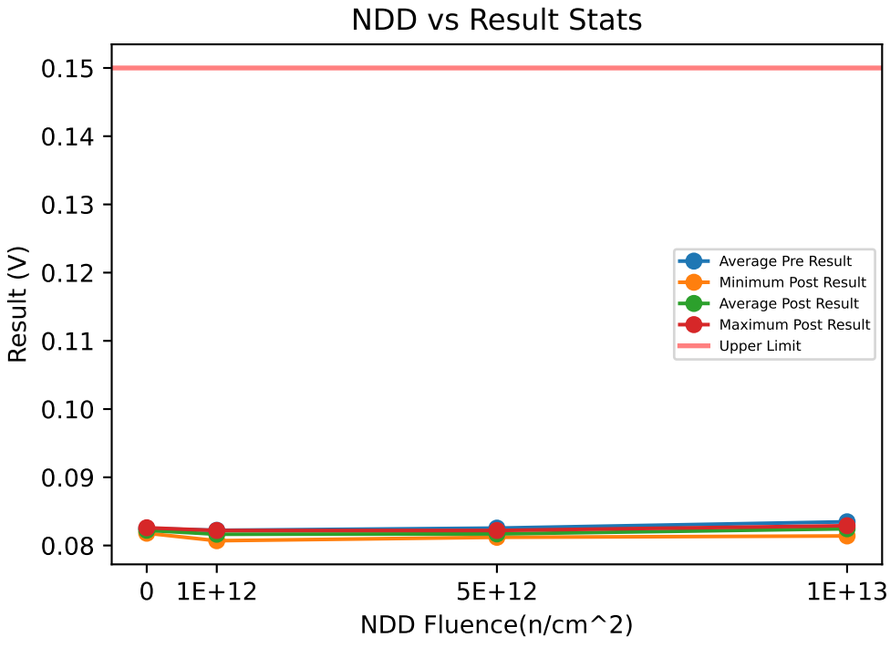
Test Results (Upper Limit = 4.7 (Ω))

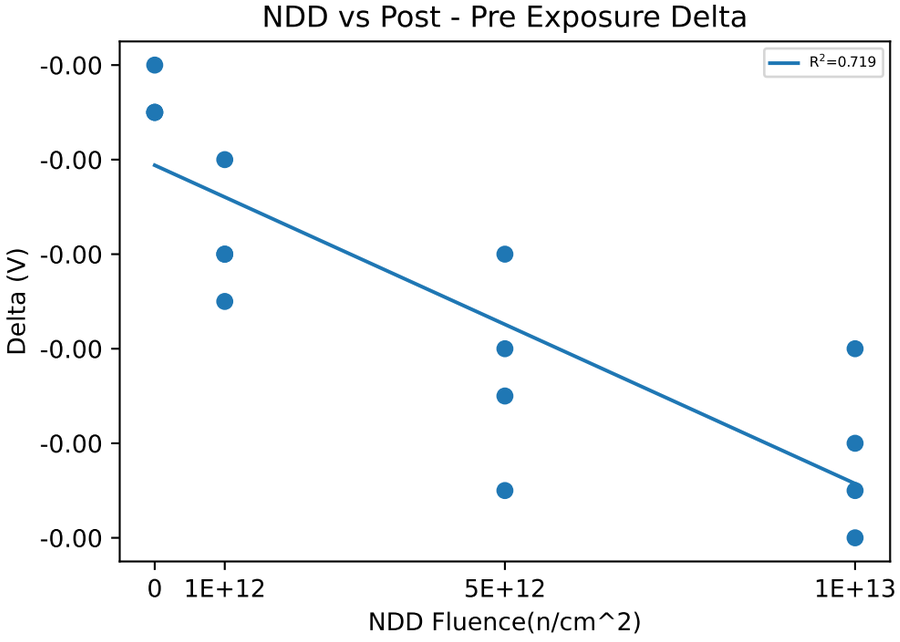
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.3048	2.3011	-0.0037
466	1e+12	NDD	2.317	2.3029	-0.0141
762	0	CORRELATION	2.3173	2.2948	-0.0225
769	1e+12	NDD	2.3092	2.2948	-0.0144
887	1e+12	NDD	2.329	2.3116	-0.0174
891	0	CORRELATION	2.3151	2.3028	-0.0123
927	1e+12	NDD	2.323	2.3102	-0.0128
967	5e+12	NDD	2.3249	2.3029	-0.022
1204	1e+13	NDD	2.3398	2.3257	-0.0141
1284	1e+13	NDD	2.3456	2.3452	-0.0004
1292	5e+12	NDD	2.3336	2.3179	-0.0157
1364	1e+13	NDD	2.3348	2.3173	-0.0175
1383	5e+12	NDD	2.3138	2.2897	-0.0241
1388	5e+12	NDD	2.2997	2.2907	-0.009
1427	1e+13	NDD	2.3476	2.3292	-0.0184
1666	0	CORRELATION	2.3209	2.3084	-0.0125

Test Statistics (Ω)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2.3048	2.3145	2.3209	0.0069101	2.2948	2.3018	2.3084	0.005599	-0.0225	-0.01275	-0.0037	0.0076861
1e+12	2.3092	2.3196	2.329	0.0084623	2.2948	2.3049	2.3116	0.0077242	-0.0174	-0.014675	-0.0128	0.0019449
5e+12	2.2997	2.318	2.3336	0.014646	2.2897	2.3003	2.3179	0.013179	-0.0241	-0.0177	-0.009	0.0068103
1e+13	2.3348	2.3419	2.3476	0.005802	2.3173	2.3293	2.3452	0.011687	-0.0184	-0.0126	-0.0004	0.0083415

Device Test: 24.1 LEVEL|LOW_LEVEL/OUTL/4.5/4.5/0/0/4.5/500kHz//@OUT_VOL





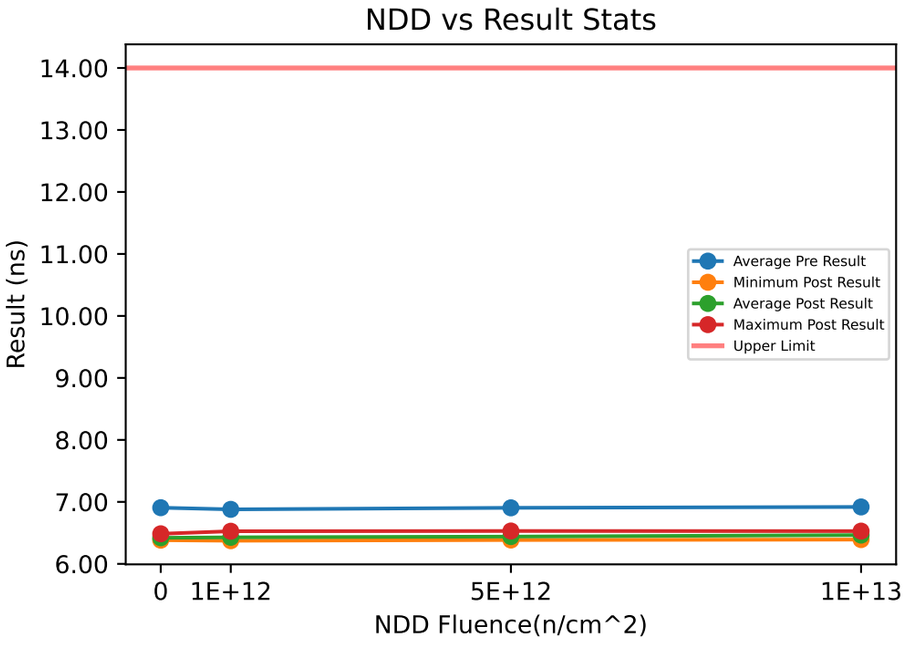
Test Results (Upper Limit = 0.15 (V))

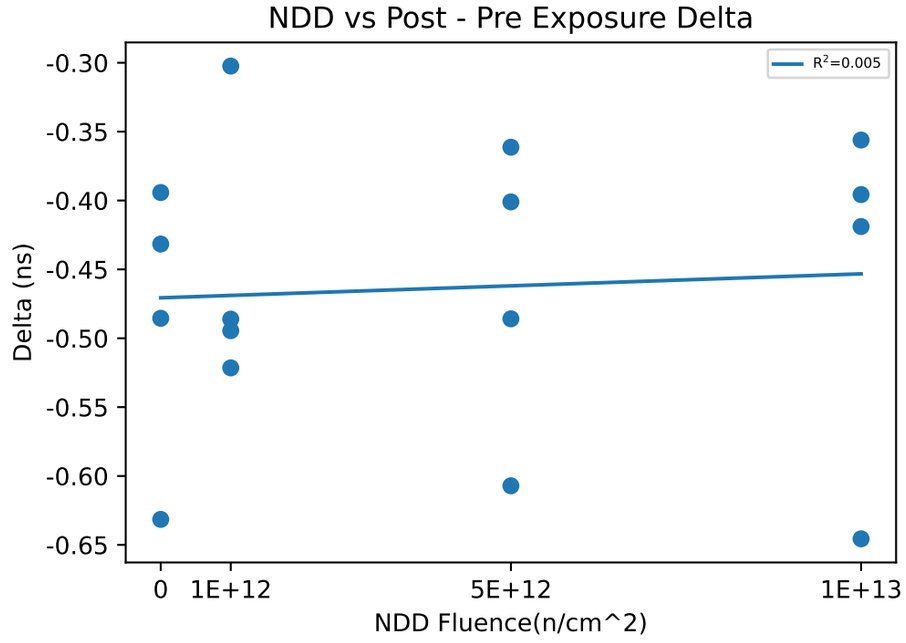
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0828	0.0826	-0.0002
466	1e+12	NDD	0.0813	0.0807	-0.0006
762	0	CORRELATION	0.0828	0.0825	-0.0003
769	1e+12	NDD	0.0826	0.082	-0.0006
887	1e+12	NDD	0.0824	0.0817	-0.0007
891	0	CORRELATION	0.0823	0.082	-0.0003
927	1e+12	NDD	0.0826	0.0822	-0.0004
967	5e+12	NDD	0.0828	0.082	-0.0008
1204	1e+13	NDD	0.0839	0.0828	-0.0011
1284	1e+13	NDD	0.0839	0.0827	-0.0012
1292	5e+12	NDD	0.0833	0.0822	-0.0011
1364	1e+13	NDD	0.0837	0.0829	-0.0008
1383	5e+12	NDD	0.082	0.0814	-0.0006
1388	5e+12	NDD	0.0821	0.0812	-0.0009
1427	1e+13	NDD	0.0824	0.0814	-0.001
1666	0	CORRELATION	0.0821	0.0818	-0.0003

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0821	0.0825	0.0828	0.0003559	0.0818	0.082225	0.0826	0.00038622	-0.0003	-0.000275	-0.0002	5e-05
1e+12	0.0813	0.082225	0.0826	0.00062383	0.0807	0.08165	0.0822	0.00066583	-0.0007	-0.000575	-0.0004	0.00012583
5e+12	0.082	0.08255	0.0833	0.00061373	0.0812	0.0817	0.0822	0.0004761	-0.0011	-0.00085	-0.0006	0.00020817
1e+13	0.0824	0.083475	0.0839	0.00072284	0.0814	0.08245	0.0829	0.00070475	-0.0012	-0.001025	-0.0008	0.00017078

Device Test: 24.10 TIMING|OUT_FALL/OUTH/4.5/4.5/0/1000/4.5/500kHz//@OUT_FALL_4P5V





Test Results (Upper Limit = 14.0 (ns))

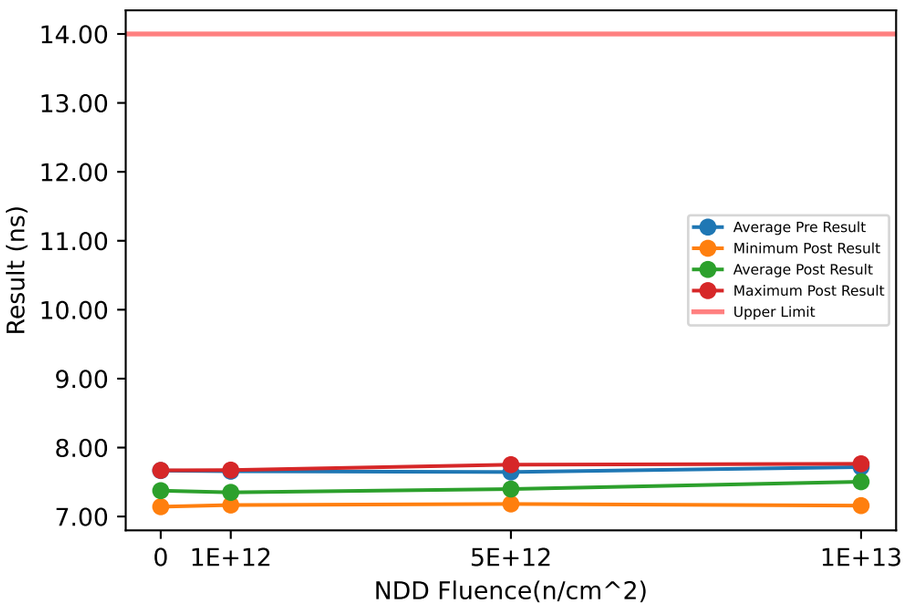
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	6.897	6.4115	-0.4855
466	1e+12	NDD	6.8679	6.3734	-0.4945
762	0	CORRELATION	7.0344	6.4029	-0.6315
769	1e+12	NDD	6.7041	6.4017	-0.3024
887	1e+12	NDD	7.0125	6.5264	-0.4861
891	0	CORRELATION	6.9168	6.4852	-0.4316
927	1e+12	NDD	6.9325	6.411	-0.5215
967	5e+12	NDD	6.7887	6.4274	-0.3613
1204	1e+13	NDD	6.9473	6.5284	-0.4189
1284	1e+13	NDD	6.9078	6.5121	-0.3957
1292	5e+12	NDD	6.9312	6.5302	-0.401
1364	1e+13	NDD	6.7809	6.4248	-0.3561
1383	5e+12	NDD	7.0259	6.4188	-0.6071
1388	5e+12	NDD	6.8706	6.3847	-0.4859
1427	1e+13	NDD	7.0372	6.3916	-0.6456
1666	0	CORRELATION	6.7763	6.3821	-0.3942

Test Statistics (ns)

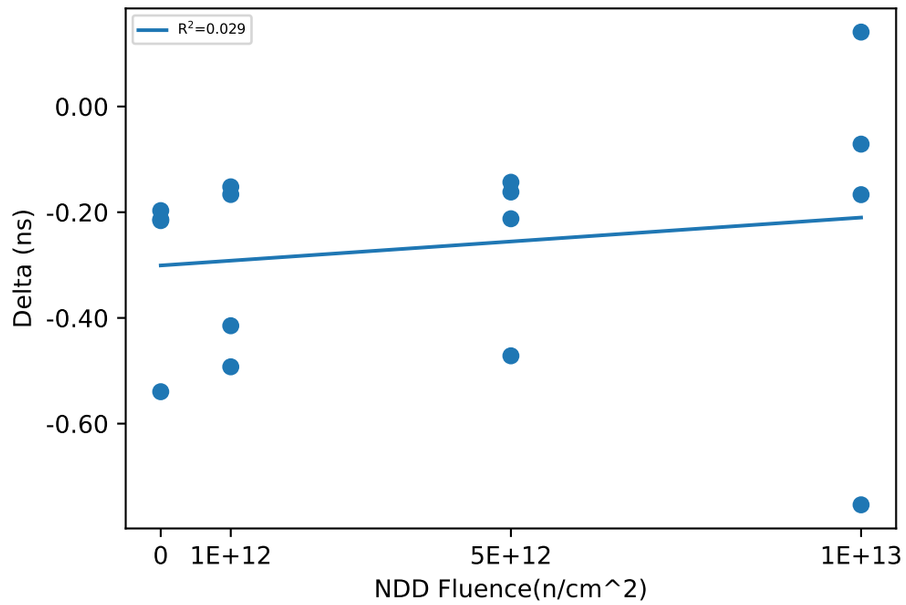
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.7763	6.9061	7.0344	0.10568	6.3821	6.4204	6.4852	0.044912	-0.6315	-0.4857	-0.3942	0.10417
1e+12	6.7041	6.8792	7.0125	0.13089	6.3734	6.4281	6.5264	0.06744	-0.5215	-0.45113	-0.3024	0.10029
5e+12	6.7887	6.9041	7.0259	0.10002	6.3847	6.4403	6.5302	0.062722	-0.6071	-0.46383	-0.3613	0.10874
1e+13	6.7809	6.9183	7.0372	0.10641	6.3916	6.4642	6.5284	0.066431	-0.6456	-0.45407	-0.3561	0.13029

Device Test: 24.11 TIMING|OUT_RISE/OUTH/5/5/0/1000/5/500kHz//@OUT_RISE_5V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 14.0 (ns))

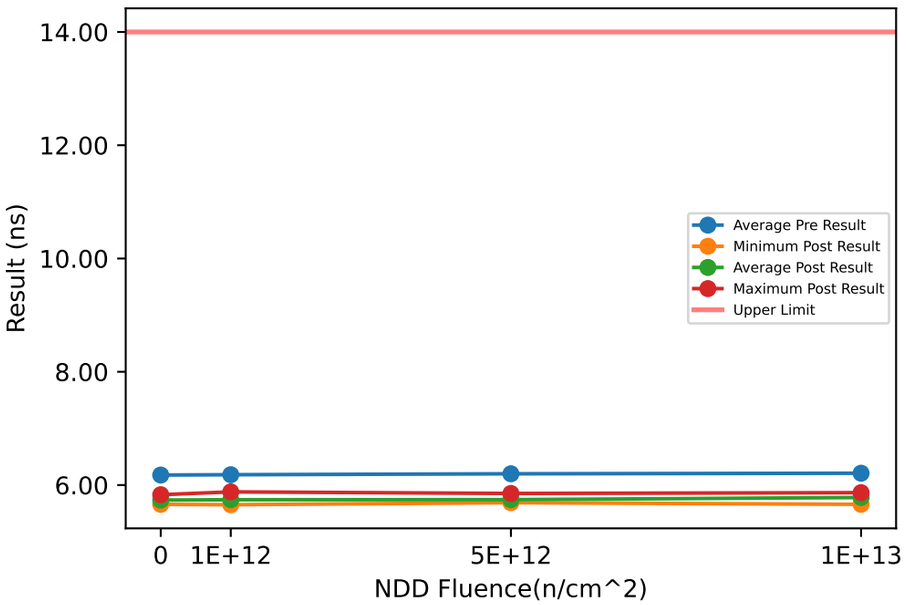
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.5671	7.3512	-0.2159
466	1e+12	NDD	7.5812	7.1664	-0.4148
762	0	CORRELATION	7.8762	7.3366	-0.5396
769	1e+12	NDD	7.3742	7.2077	-0.1665
887	1e+12	NDD	7.8254	7.6734	-0.152
891	0	CORRELATION	7.8831	7.6696	-0.2135
927	1e+12	NDD	7.8451	7.3526	-0.4925
967	5e+12	NDD	7.3436	7.1818	-0.1618
1204	1e+13	NDD	7.9313	7.7645	-0.1668
1284	1e+13	NDD	7.5973	7.7381	0.1408
1292	5e+12	NDD	7.8952	7.7519	-0.1433
1364	1e+13	NDD	7.4276	7.3564	-0.0712
1383	5e+12	NDD	7.8042	7.3325	-0.4717
1388	5e+12	NDD	7.5393	7.3269	-0.2124
1427	1e+13	NDD	7.9116	7.158	-0.7536
1666	0	CORRELATION	7.339	7.142	-0.197

Test Statistics (ns)

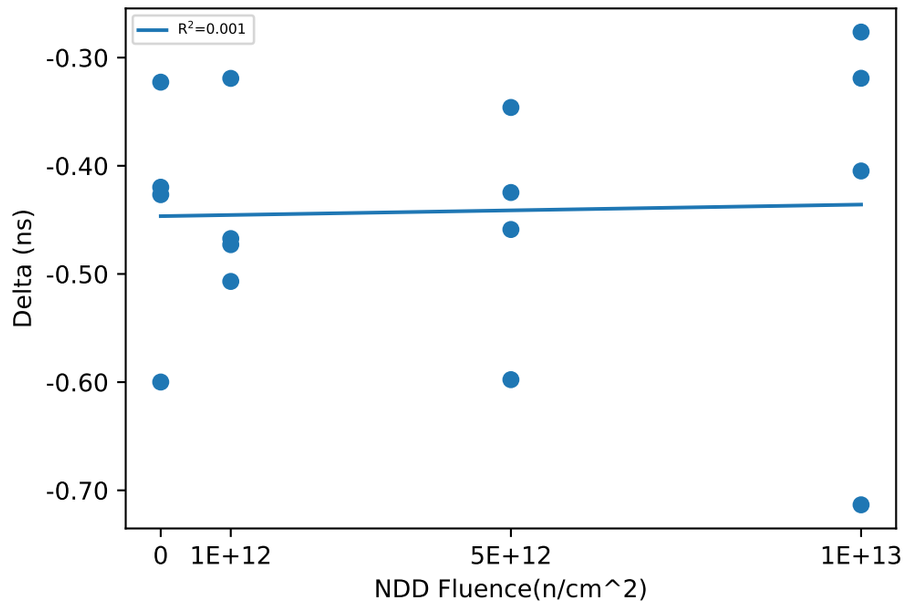
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.339	7.6663	7.8831	0.26333	7.142	7.3749	7.6696	0.21842	-0.5396	-0.2915	-0.197	0.16561
1e+12	7.3742	7.6565	7.8451	0.2232	7.1664	7.35	7.6734	0.22989	-0.4925	-0.30645	-0.152	0.17301
5e+12	7.3436	7.6456	7.8952	0.25163	7.1818	7.3983	7.7519	0.24585	-0.4717	-0.2473	-0.1433	0.15242
1e+13	7.4276	7.7169	7.9313	0.24622	7.158	7.5042	7.7645	0.29674	-0.7536	-0.2127	0.1408	0.38282

Device Test: 24.12 TIMING|OUT_FALL/OUTH/5/5/0/1000/5/500kHz//@OUT_FALL_5V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 14.0 (ns))

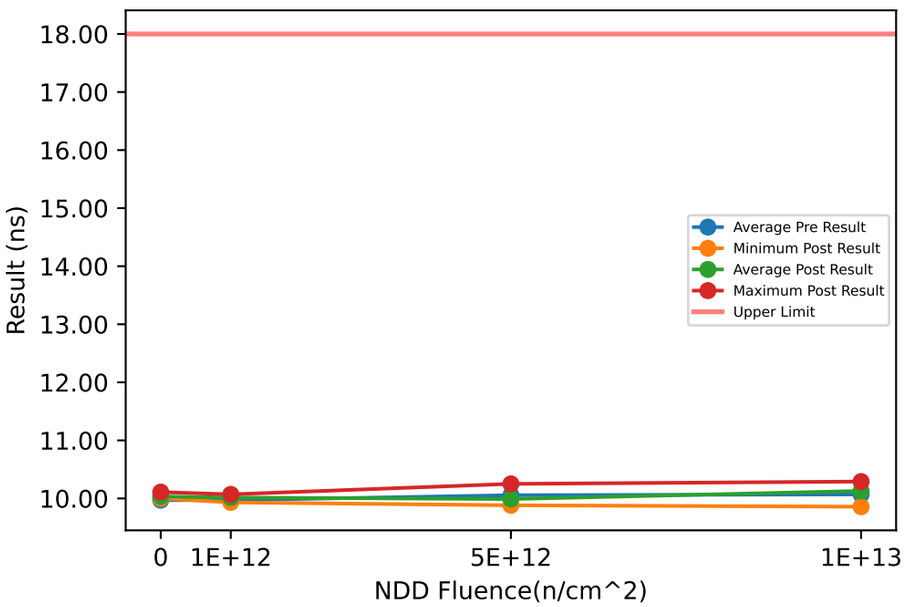
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	6.1347	5.7149	-0.4198
466	1e+12	NDD	6.12	5.6527	-0.4673
762	0	CORRELATION	6.3341	5.7342	-0.5999
769	1e+12	NDD	6.0037	5.6845	-0.3192
887	1e+12	NDD	6.3523	5.8794	-0.4729
891	0	CORRELATION	6.256	5.8293	-0.4267
927	1e+12	NDD	6.2529	5.746	-0.5069
967	5e+12	NDD	6.0346	5.6885	-0.3461
1204	1e+13	NDD	6.2701	5.8653	-0.4048
1284	1e+13	NDD	6.1664	5.8473	-0.3191
1292	5e+12	NDD	6.2763	5.8516	-0.4247
1364	1e+13	NDD	6.0256	5.7492	-0.2764
1383	5e+12	NDD	6.337	5.7393	-0.5977
1388	5e+12	NDD	6.1475	5.6886	-0.4589
1427	1e+13	NDD	6.373	5.6596	-0.7134
1666	0	CORRELATION	5.9818	5.6591	-0.3227

Test Statistics (ns)

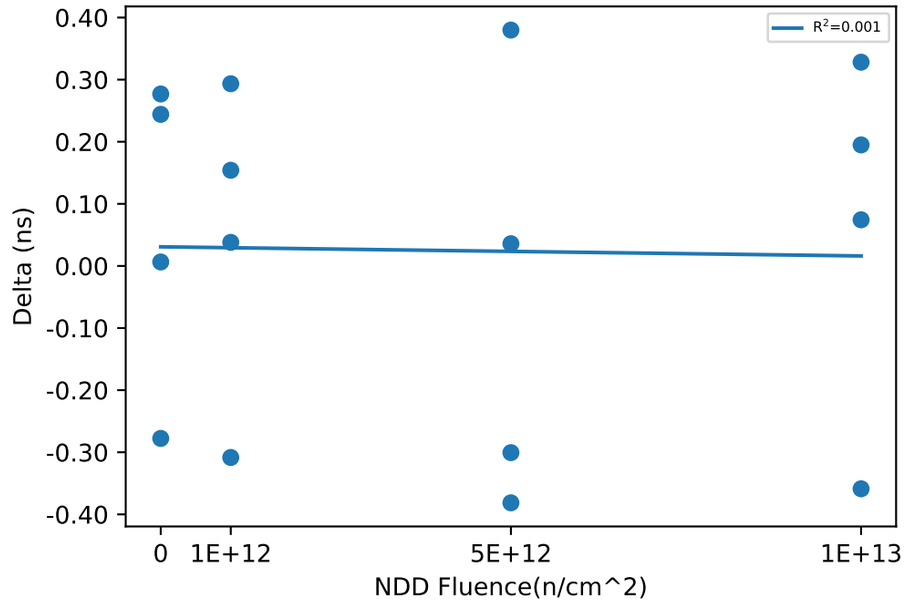
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.9818	6.1767	6.3341	0.15364	5.6591	5.7344	5.8293	0.070843	-0.5999	-0.44227	-0.3227	0.11531
1e+12	6.0037	6.1822	6.3523	0.15239	5.6527	5.7407	5.8794	0.10028	-0.5069	-0.44157	-0.3192	0.083439
5e+12	6.0346	6.1989	6.337	0.13503	5.6885	5.742	5.8516	0.076884	-0.5977	-0.45685	-0.3461	0.10511
1e+13	6.0256	6.2088	6.373	0.14841	5.6596	5.7804	5.8653	0.095306	-0.7134	-0.42843	-0.2764	0.19734

Device Test: 24.13 TIMING|OUT_RISE/OUTH/12/12/0/1000/5/500kHz//@OUT_RISE_12V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 18.0 (ns))

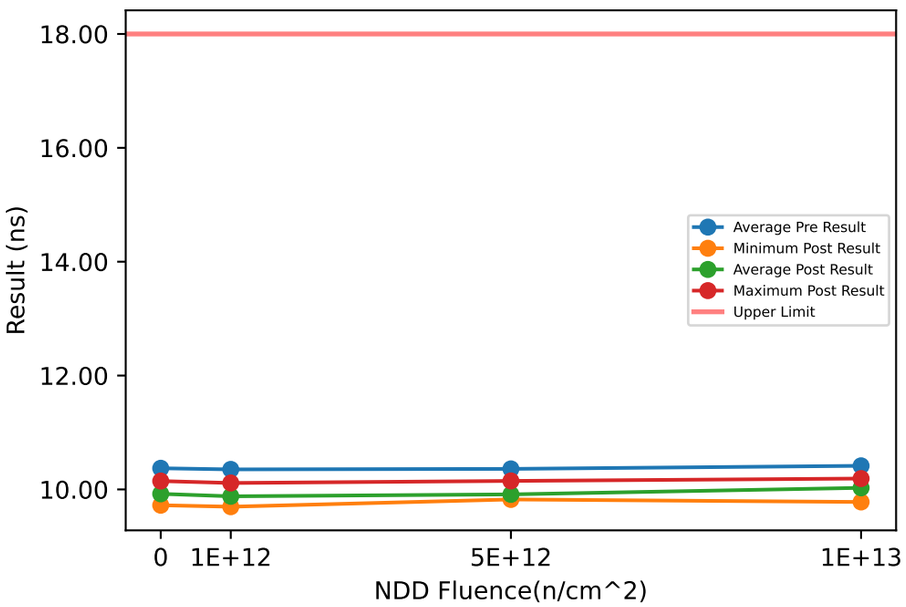
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	10.284	10.007	-0.2777
466	1e+12	NDD	9.8783	10.032	0.1541
762	0	CORRELATION	10.011	10.017	0.0064
769	1e+12	NDD	10.24	9.9317	-0.3084
887	1e+12	NDD	10.032	10.07	0.038
891	0	CORRELATION	9.7237	10.001	0.2769
927	1e+12	NDD	9.7312	10.025	0.2934
967	5e+12	NDD	10.264	9.8821	-0.3814
1204	1e+13	NDD	9.9253	10.253	0.3281
1284	1e+13	NDD	10.216	9.8574	-0.3588
1292	5e+12	NDD	9.8712	10.251	0.3798
1364	1e+13	NDD	9.9194	10.114	0.1949
1383	5e+12	NDD	9.875	9.9108	0.0358
1388	5e+12	NDD	10.214	9.9134	-0.3006
1427	1e+13	NDD	10.217	10.291	0.0743
1666	0	CORRELATION	9.8652	10.109	0.2441

Test Statistics (ns)

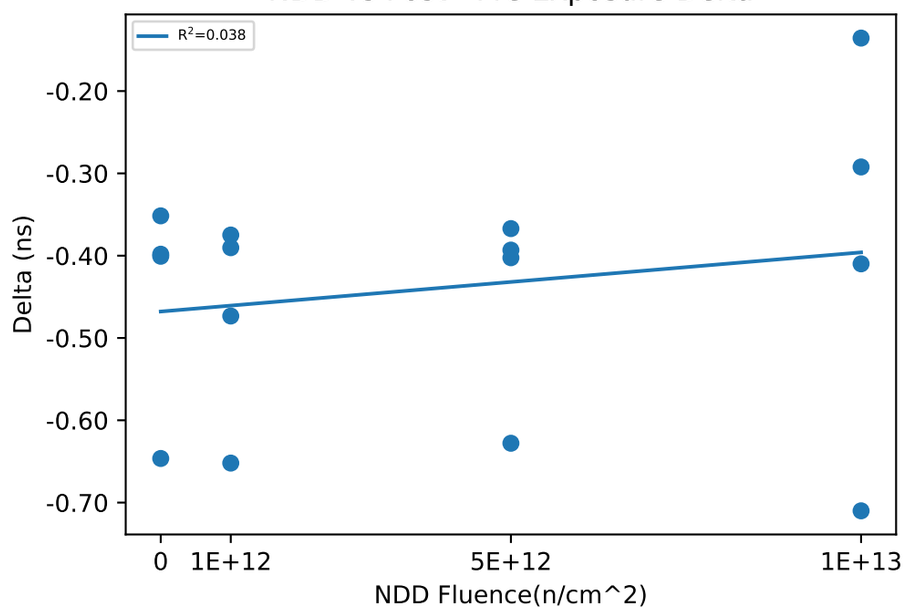
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.7237	9.971	10.284	0.23959	10.001	10.033	10.109	0.051012	-0.2777	0.062425	0.2769	0.25679
1e+12	9.7312	9.9704	10.24	0.21776	9.9317	10.015	10.07	0.058823	-0.3084	0.044275	0.2934	0.25726
5e+12	9.8712	10.056	10.264	0.21208	9.8821	9.9893	10.251	0.17503	-0.3814	-0.0666	0.3798	0.34814
1e+13	9.9194	10.069	10.217	0.16979	9.8574	10.129	10.291	0.19636	-0.3588	0.059625	0.3281	0.29759

Device Test: 24.14 TIMING|OUT_FALL/OUTH/12/12/0/1000/5/500kHz//@OUT_FALL_12V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



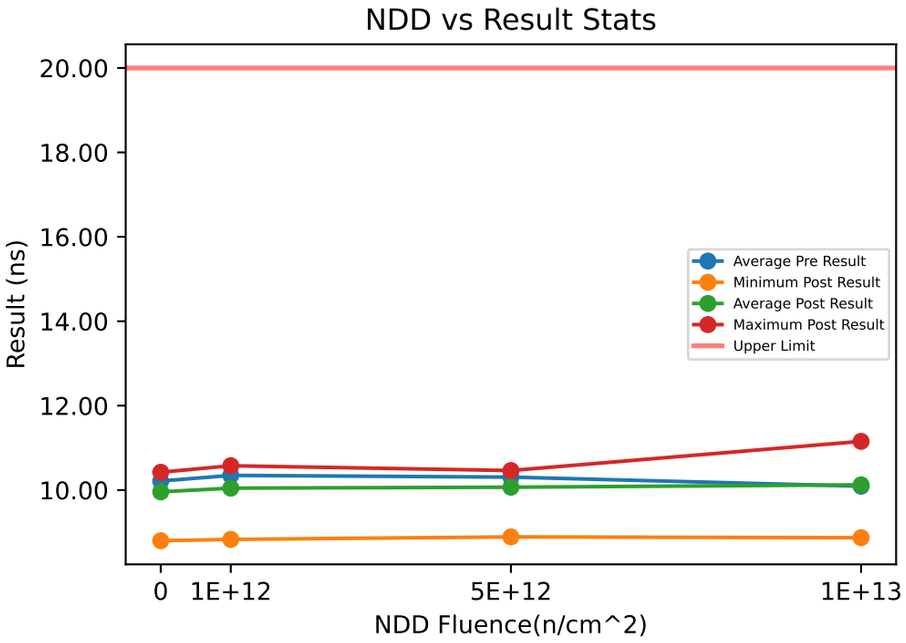
Test Results (Upper Limit = 18.0 (ns))

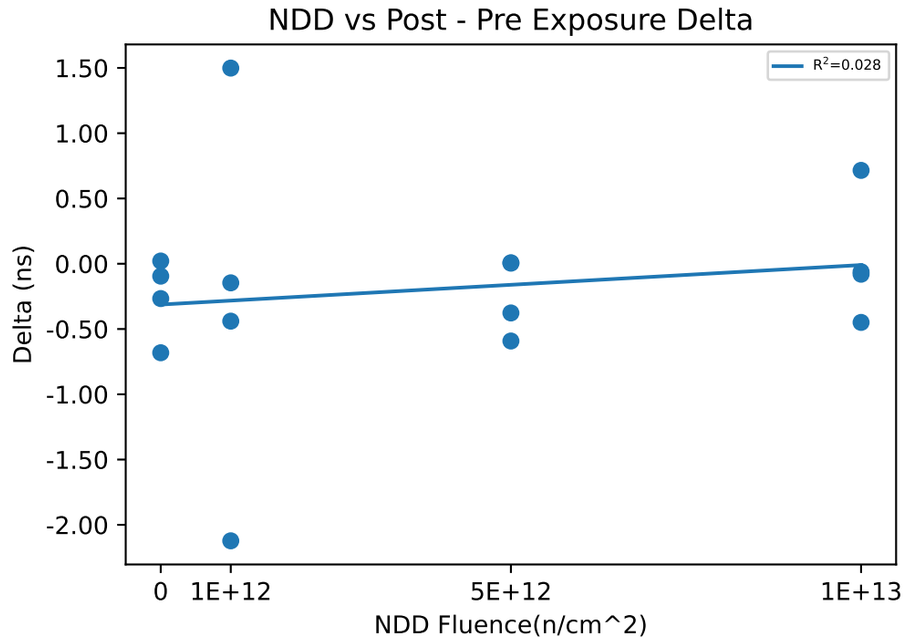
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	10.332	9.9807	-0.3516
466	1e+12	NDD	10.169	9.6962	-0.4733
762	0	CORRELATION	10.486	9.8394	-0.6464
769	1e+12	NDD	10.18	9.7892	-0.3903
887	1e+12	NDD	10.488	10.113	-0.3749
891	0	CORRELATION	10.548	10.147	-0.4007
927	1e+12	NDD	10.57	9.9181	-0.652
967	5e+12	NDD	10.221	9.8536	-0.3671
1204	1e+13	NDD	10.593	10.183	-0.4099
1284	1e+13	NDD	10.326	10.191	-0.1356
1292	5e+12	NDD	10.552	10.149	-0.4025
1364	1e+13	NDD	10.249	9.9571	-0.2922
1383	5e+12	NDD	10.453	9.8251	-0.6279
1388	5e+12	NDD	10.217	9.8239	-0.3932
1427	1e+13	NDD	10.49	9.7798	-0.71
1666	0	CORRELATION	10.121	9.7225	-0.3982

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	10.121	10.372	10.548	0.19025	9.7225	9.9224	10.147	0.18325	-0.6464	-0.44922	-0.3516	0.13338
1e+12	10.169	10.352	10.57	0.20744	9.6962	9.8791	10.113	0.18052	-0.652	-0.47263	-0.3749	0.12715
5e+12	10.217	10.361	10.552	0.16854	9.8239	9.913	10.149	0.1581	-0.6279	-0.44767	-0.3671	0.12108
1e+13	10.249	10.415	10.593	0.15549	9.7798	10.028	10.191	0.19756	-0.71	-0.38693	-0.1356	0.24293

Device Test: 24.15 TIMING|OUT_RISE/OUTH/14/14/0/1000/5/500kHz//@OUT_RISE_14V





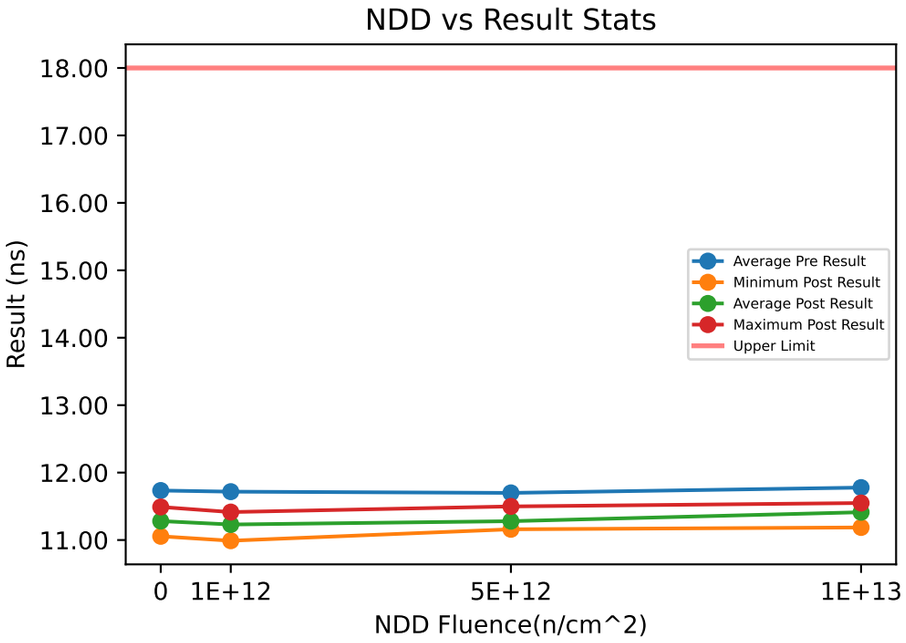
Test Results (Upper Limit = 20.0 (ns))

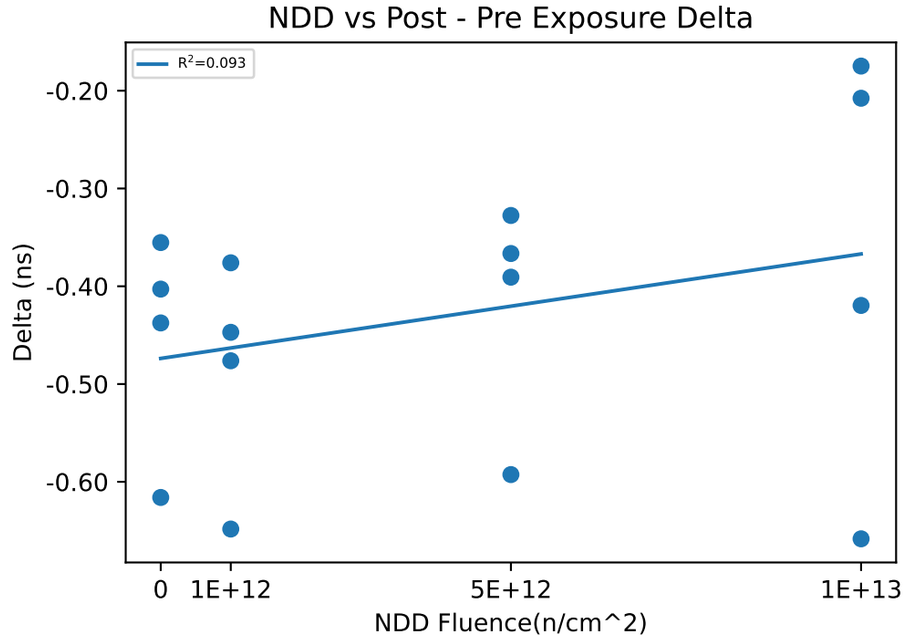
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	11.037	10.356	-0.6818
466	1e+12	NDD	10.851	10.411	-0.4397
762	0	CORRELATION	10.401	10.422	0.0209
769	1e+12	NDD	10.723	10.577	-0.1463
887	1e+12	NDD	10.954	8.8317	-2.1225
891	0	CORRELATION	8.8954	8.8004	-0.095
927	1e+12	NDD	8.8648	10.364	1.4989
967	5e+12	NDD	10.835	10.458	-0.377
1204	1e+13	NDD	8.9519	8.8717	-0.0802
1284	1e+13	NDD	10.439	11.154	0.7152
1292	5e+12	NDD	8.8831	8.8905	0.0074
1364	1e+13	NDD	10.385	10.324	-0.0612
1383	5e+12	NDD	10.456	10.46	0.0046
1388	5e+12	NDD	11.055	10.463	-0.5919
1427	1e+13	NDD	10.594	10.145	-0.4494
1666	0	CORRELATION	10.521	10.254	-0.2668

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.8954	10.214	11.037	0.92122	8.8004	9.9581	10.422	0.77488	-0.6818	-0.25568	0.0209	0.30769
1e+12	8.8648	10.348	10.954	0.9934	8.8317	10.046	10.577	0.81448	-2.1225	-0.3024	1.4989	1.4833
5e+12	8.8831	10.307	11.055	0.98123	8.8905	10.068	10.463	0.78504	-0.5919	-0.23923	0.0074	0.29644
1e+13	8.9519	10.092	10.594	0.7655	8.8717	10.124	11.154	0.94334	-0.4494	0.0311	0.7152	0.48982

Device Test: 24.16 TIMING|OUT_FALL/OUTH/14/14/0/1000/5/500kHz//@OUT_FALL_14V





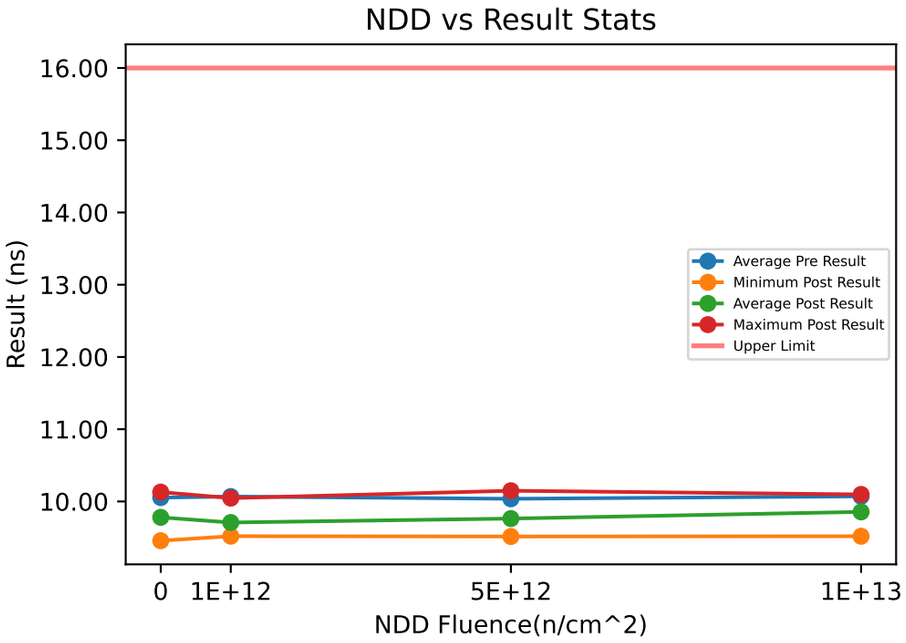
Test Results (Upper Limit = 18.0 (ns))

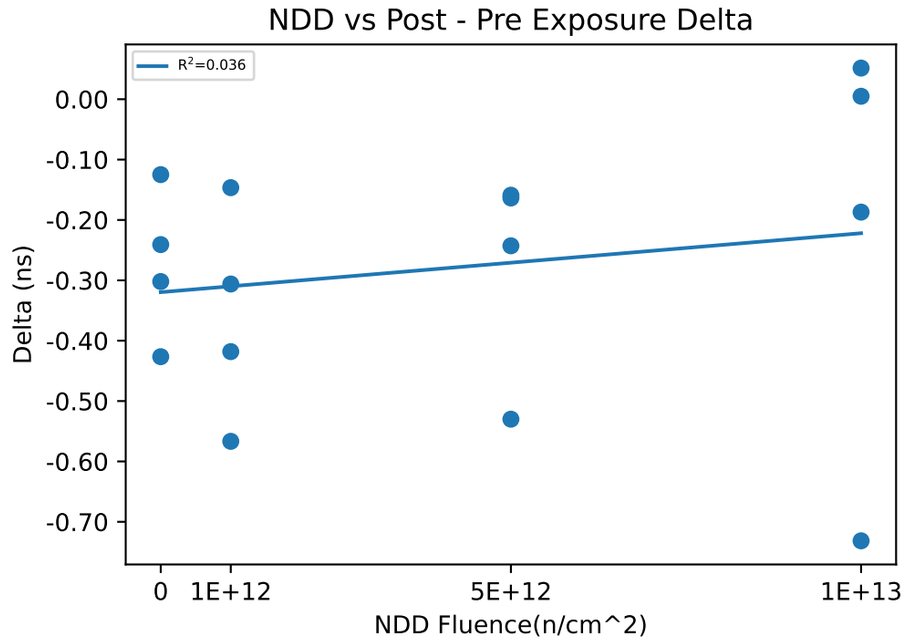
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	11.774	11.371	-0.4029
466	1e+12	NDD	11.466	10.99	-0.4762
762	0	CORRELATION	11.824	11.208	-0.616
769	1e+12	NDD	11.575	11.199	-0.376
887	1e+12	NDD	11.862	11.415	-0.4471
891	0	CORRELATION	11.928	11.49	-0.4375
927	1e+12	NDD	11.966	11.318	-0.6483
967	5e+12	NDD	11.613	11.285	-0.3276
1204	1e+13	NDD	11.968	11.549	-0.4196
1284	1e+13	NDD	11.716	11.541	-0.1748
1292	5e+12	NDD	11.889	11.498	-0.3907
1364	1e+13	NDD	11.581	11.373	-0.2077
1383	5e+12	NDD	11.768	11.175	-0.5926
1388	5e+12	NDD	11.526	11.159	-0.3665
1427	1e+13	NDD	11.845	11.186	-0.6583
1666	0	CORRELATION	11.411	11.056	-0.3553

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	11.411	11.734	11.928	0.22477	11.056	11.281	11.49	0.18976	-0.616	-0.45293	-0.3553	0.11382
1e+12	11.466	11.717	11.966	0.23549	10.99	11.23	11.415	0.18304	-0.6483	-0.4869	-0.376	0.11554
5e+12	11.526	11.699	11.889	0.16147	11.159	11.279	11.498	0.15631	-0.5926	-0.41935	-0.3276	0.11839
1e+13	11.581	11.777	11.968	0.16668	11.186	11.412	11.549	0.17106	-0.6583	-0.3651	-0.1748	0.22355

Device Test: 24.17 TIMING|OUT_RISE/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_RISE_LDO





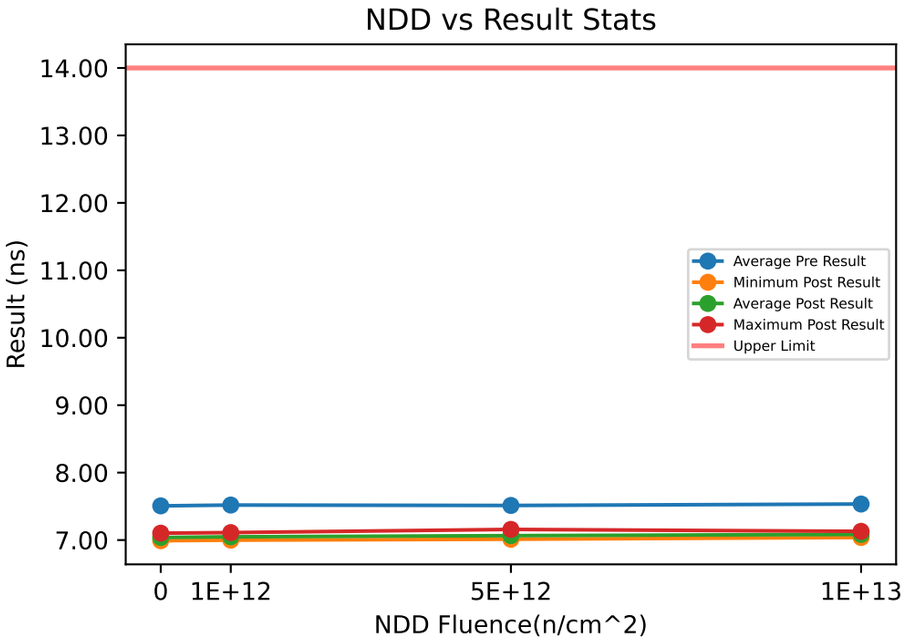
Test Results (Upper Limit = 16.0 (ns))

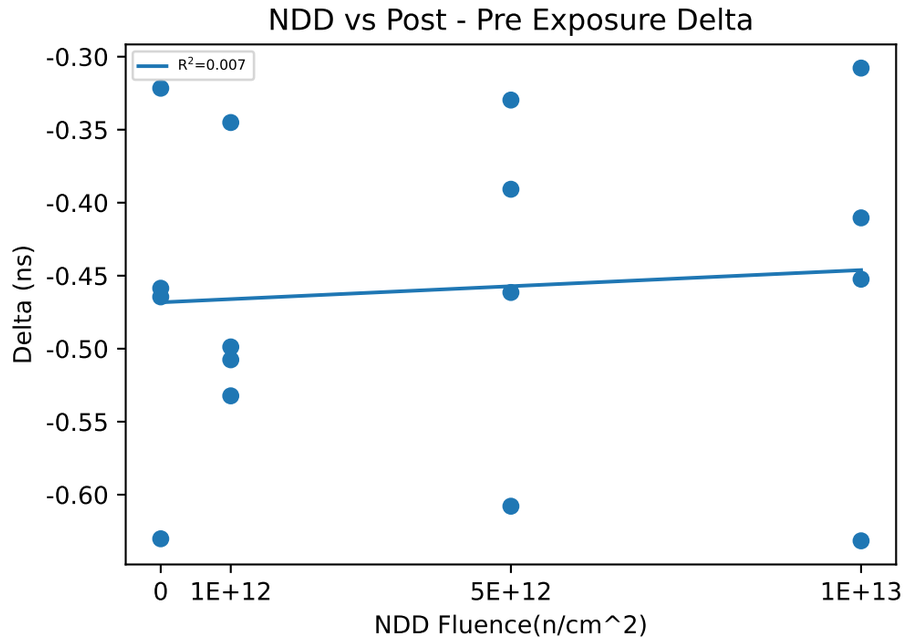
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	10.007	9.7664	-0.2408
466	1e+12	NDD	9.953	9.5349	-0.4181
762	0	CORRELATION	10.194	9.767	-0.4265
769	1e+12	NDD	9.8254	9.5193	-0.3061
887	1e+12	NDD	10.193	10.046	-0.1465
891	0	CORRELATION	10.255	10.13	-0.1249
927	1e+12	NDD	10.3	9.7338	-0.5667
967	5e+12	NDD	9.6785	9.5149	-0.1636
1204	1e+13	NDD	10.284	10.097	-0.187
1284	1e+13	NDD	9.9789	10.03	0.0516
1292	5e+12	NDD	10.307	10.148	-0.159
1364	1e+13	NDD	9.7712	9.7761	0.0049
1383	5e+12	NDD	10.248	9.7183	-0.53
1388	5e+12	NDD	9.9141	9.6713	-0.2428
1427	1e+13	NDD	10.25	9.5184	-0.7315
1666	0	CORRELATION	9.7586	9.4566	-0.302

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	9.7586	10.053	10.255	0.22297	9.4566	9.7799	10.13	0.27522	-0.4265	-0.27355	-0.1249	0.12566
1e+12	9.8254	10.068	10.3	0.21738	9.5193	9.7086	10.046	0.2455	-0.5667	-0.35935	-0.1465	0.17756
5e+12	9.6785	10.037	10.307	0.29509	9.5149	9.7631	10.148	0.27096	-0.53	-0.27385	-0.159	0.17505
1e+13	9.7712	10.071	10.284	0.24215	9.5184	9.8556	10.097	0.264	-0.7315	-0.2155	0.0516	0.35916

Device Test: 24.18 TIMING|OUT_FALL/OUTH/4.5/12/0/1000/4.5/500kHz//@OUT_FALL_LDO





Test Results (Upper Limit = 14.0 (ns))

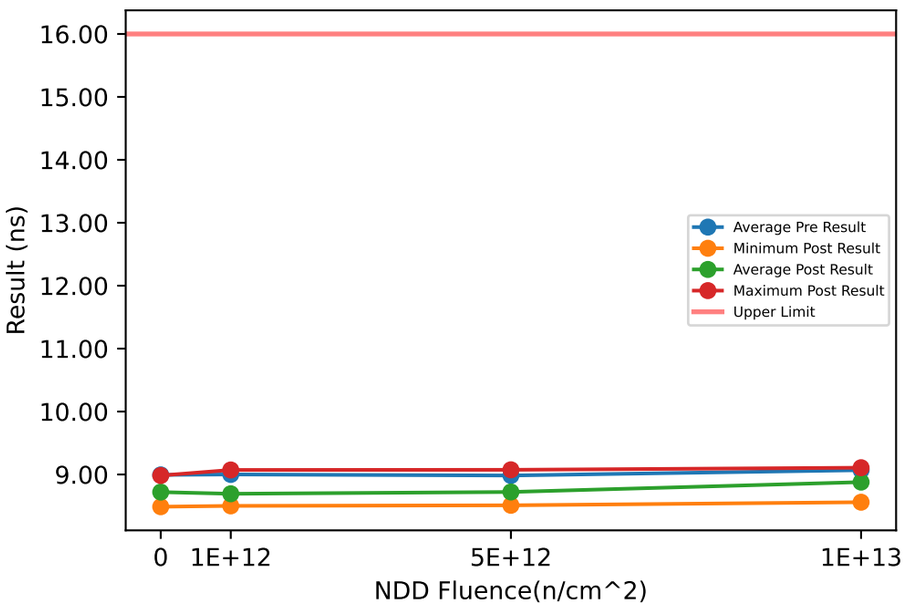
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.5235	7.059	-0.4645
466	1e+12	NDD	7.4972	6.9984	-0.4988
762	0	CORRELATION	7.6314	7.0012	-0.6302
769	1e+12	NDD	7.3856	7.0405	-0.3451
887	1e+12	NDD	7.6427	7.1104	-0.5323
891	0	CORRELATION	7.5606	7.102	-0.4586
927	1e+12	NDD	7.5499	7.0423	-0.5076
967	5e+12	NDD	7.3899	7.0602	-0.3297
1204	1e+13	NDD	7.5816	7.1292	-0.4524
1284	1e+13	NDD	7.5329	7.1225	-0.4104
1292	5e+12	NDD	7.5484	7.1576	-0.3908
1364	1e+13	NDD	7.352	7.0442	-0.3078
1383	5e+12	NDD	7.639	7.0311	-0.6079
1388	5e+12	NDD	7.4736	7.0121	-0.4615
1427	1e+13	NDD	7.6697	7.0381	-0.6316
1666	0	CORRELATION	7.3116	6.99	-0.3216

Test Statistics (ns)

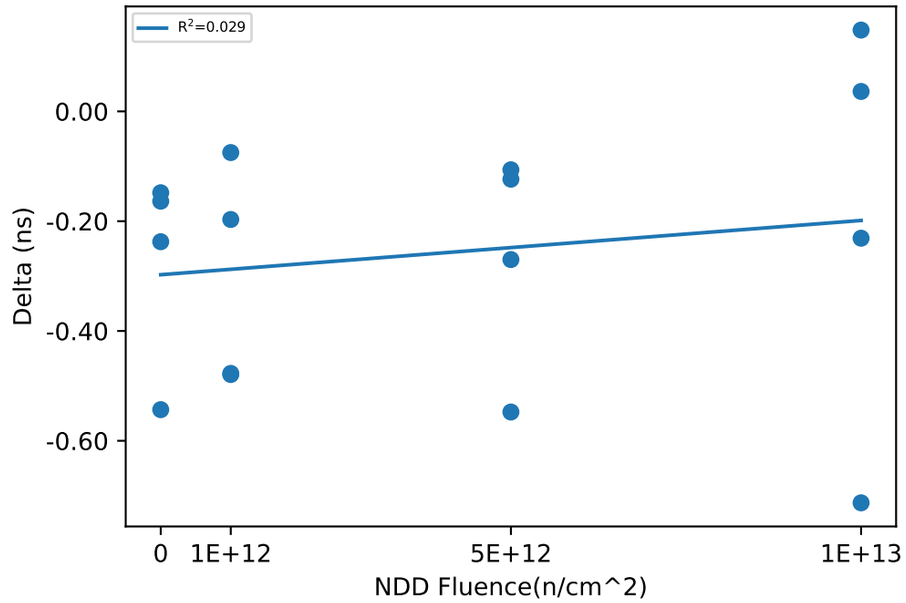
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.3116	7.5068	7.6314	0.1376	6.99	7.0381	7.102	0.052266	-0.6302	-0.46873	-0.3216	0.12628
1e+12	7.3856	7.5189	7.6427	0.10728	6.9984	7.0479	7.1104	0.046342	-0.5323	-0.47095	-0.3451	0.08509
5e+12	7.3899	7.5127	7.639	0.1062	7.0121	7.0653	7.1576	0.064666	-0.6079	-0.44747	-0.3297	0.11974
1e+13	7.352	7.534	7.6697	0.13392	7.0381	7.0835	7.1292	0.049041	-0.6316	-0.45055	-0.3078	0.13512

Device Test: 24.19 TIMING|OUT_RISE/OUTH/5/12/0/1000/5/500kHz//@OUT_RISE_LDO

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 16.0 (ns))

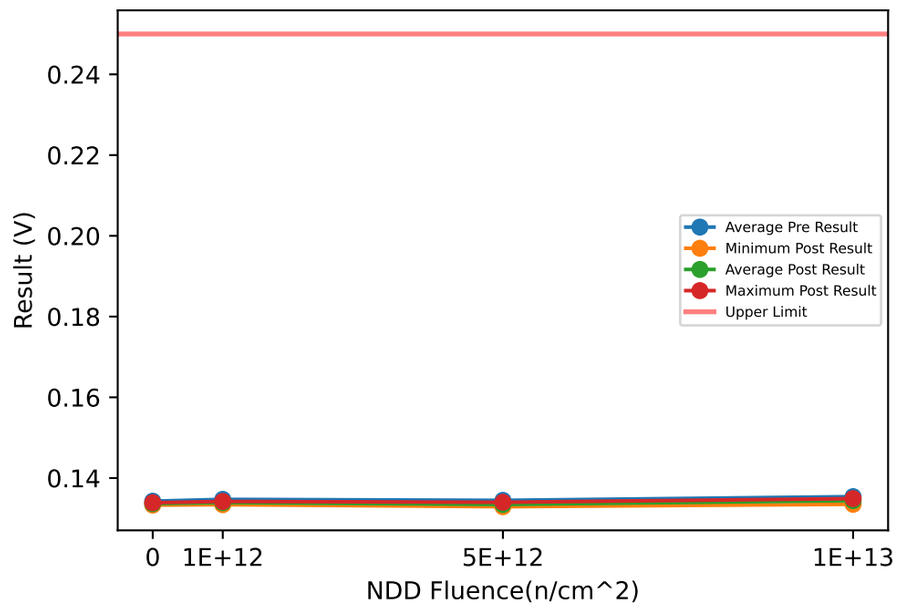
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	8.9298	8.7816	-0.1482
466	1e+12	NDD	8.9803	8.501	-0.4793
762	0	CORRELATION	9.1713	8.628	-0.5433
769	1e+12	NDD	8.7207	8.5238	-0.1969
887	1e+12	NDD	9.1467	9.0717	-0.075
891	0	CORRELATION	9.221	8.9836	-0.2374
927	1e+12	NDD	9.1542	8.6769	-0.4773
967	5e+12	NDD	8.6338	8.5103	-0.1235
1204	1e+13	NDD	9.2604	9.0294	-0.231
1284	1e+13	NDD	8.9593	9.1074	0.1481
1292	5e+12	NDD	9.1807	9.0743	-0.1064
1364	1e+13	NDD	8.7824	8.8187	0.0363
1383	5e+12	NDD	9.2385	8.6909	-0.5476
1388	5e+12	NDD	8.882	8.6121	-0.2699
1427	1e+13	NDD	9.2723	8.5593	-0.713
1666	0	CORRELATION	8.6513	8.4877	-0.1636

Test Statistics (ns)

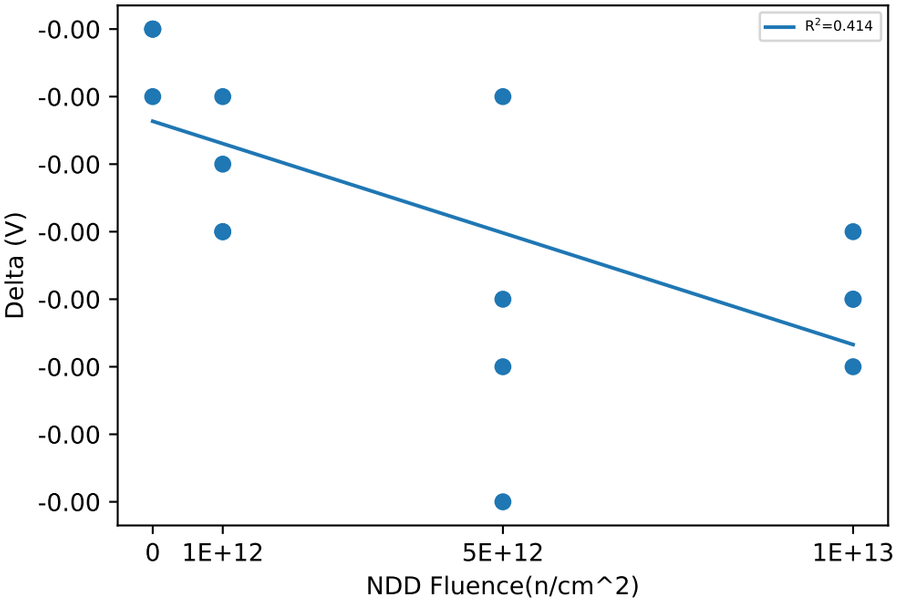
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.6513	8.9933	9.221	0.26111	8.4877	8.7202	8.9836	0.21269	-0.5433	-0.27313	-0.1482	0.18428
1e+12	8.7207	9.0005	9.1542	0.20306	8.501	8.6933	9.0717	0.26405	-0.4793	-0.30713	-0.075	0.20383
5e+12	8.6338	8.9838	9.2385	0.28078	8.5103	8.7219	9.0743	0.24629	-0.5476	-0.26185	-0.1064	0.20414
1e+13	8.7824	9.0686	9.2723	0.23954	8.5593	8.8787	9.1074	0.24538	-0.713	-0.1899	0.1481	0.38329

Device Test: 24.2 LEVEL|HIGH_LEVEL/OUTH/4.5/4.5/0/0/4.5/500kHz//@OUT_VOH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 0.25 (V))

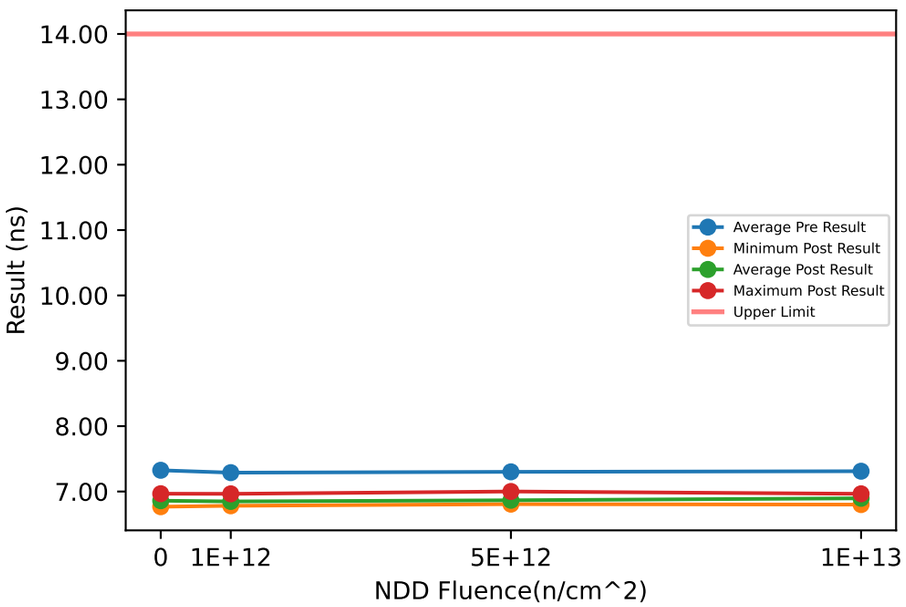
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.1339	0.1333	-0.0006
466	1e+12	NDD	0.1347	0.1339	-0.0008
762	0	CORRELATION	0.1344	0.1337	-0.0007
769	1e+12	NDD	0.1343	0.1334	-0.0009
887	1e+12	NDD	0.1351	0.1342	-0.0009
891	0	CORRELATION	0.1343	0.1337	-0.0006
927	1e+12	NDD	0.1348	0.1341	-0.0007
967	5e+12	NDD	0.1351	0.134	-0.0011
1204	1e+13	NDD	0.1355	0.1345	-0.001
1284	1e+13	NDD	0.1356	0.1347	-0.0009
1292	5e+12	NDD	0.1349	0.1339	-0.001
1364	1e+13	NDD	0.1359	0.1349	-0.001
1383	5e+12	NDD	0.1343	0.133	-0.0013
1388	5e+12	NDD	0.1336	0.1329	-0.0007
1427	1e+13	NDD	0.1346	0.1335	-0.0011
1666	0	CORRELATION	0.1345	0.1339	-0.0006

Test Statistics (V)

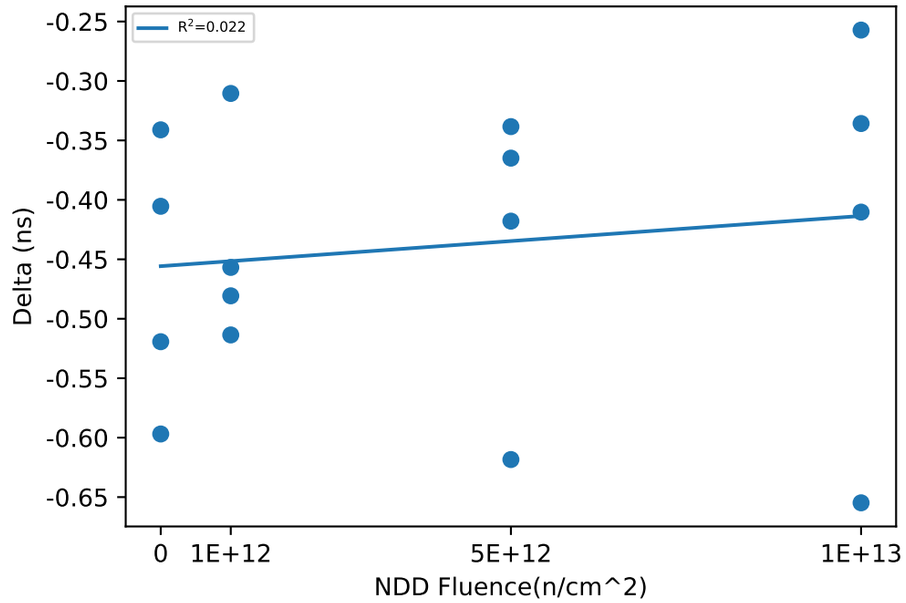
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1339	0.13428	0.1345	0.000263	0.1333	0.13365	0.1339	0.00025166	-0.0007	-0.000625	-0.0006	5e-05
1e+12	0.1343	0.13472	0.1351	0.0003304	0.1334	0.1339	0.1342	0.0003559	-0.0009	-0.000825	-0.0007	9.5743e-05
5e+12	0.1336	0.13448	0.1351	0.00067515	0.1329	0.13345	0.134	0.00058023	-0.0013	-0.001025	-0.0007	0.00025
1e+13	0.1346	0.1354	0.1359	0.00055976	0.1335	0.1344	0.1349	0.00062183	-0.0011	-0.001	-0.0009	8.165e-05

Device Test: 24.20 TIMING|OUT_FALL/OUTH/5/12/0/1000/5/500kHz//@OUT_FALL_LDO

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



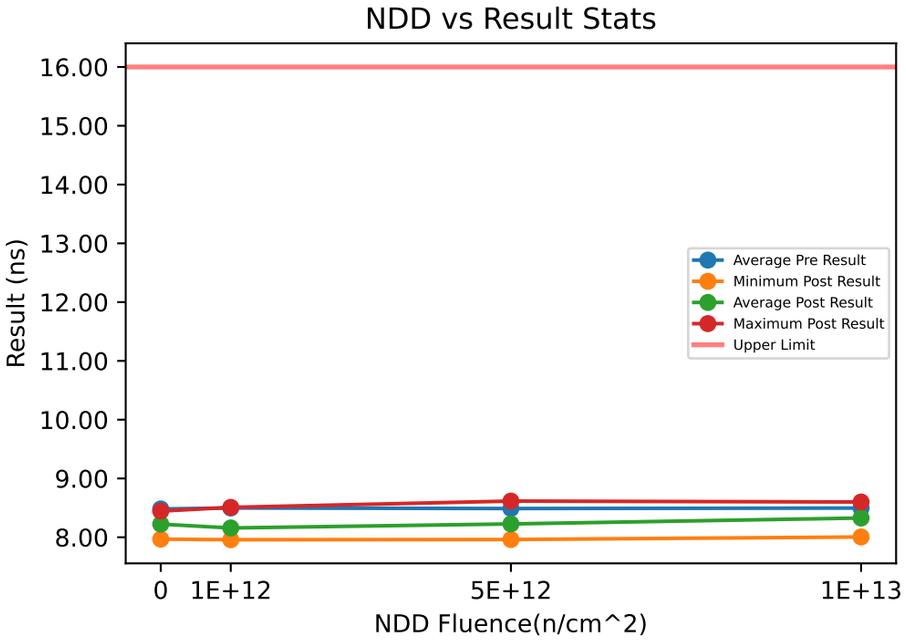
Test Results (Upper Limit = 14.0 (ns))

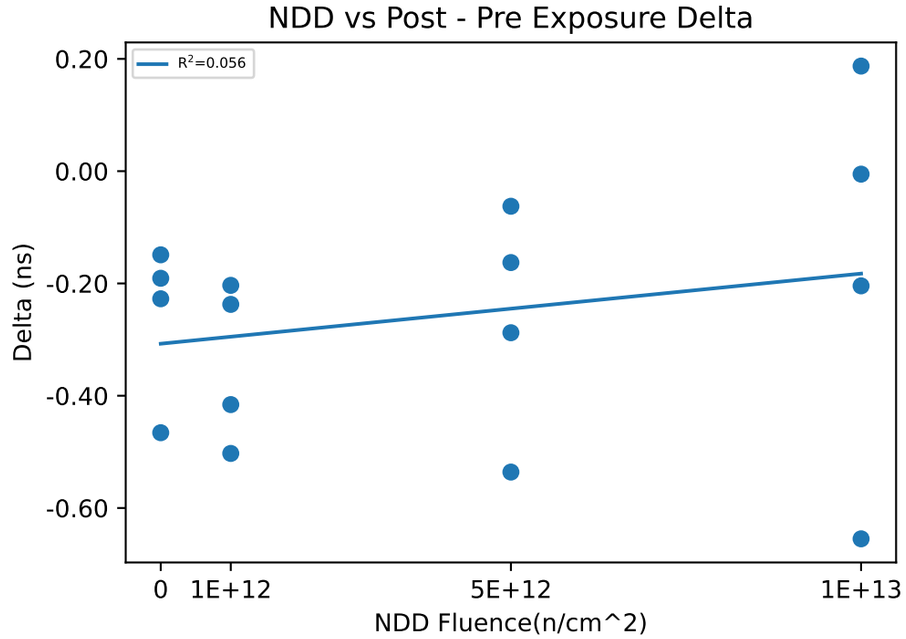
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	7.3869	6.8676	-0.5193
466	1e+12	NDD	7.2384	6.7816	-0.4568
762	0	CORRELATION	7.4326	6.8357	-0.5969
769	1e+12	NDD	7.1128	6.8023	-0.3105
887	1e+12	NDD	7.4452	6.9645	-0.4807
891	0	CORRELATION	7.3718	6.9664	-0.4054
927	1e+12	NDD	7.3584	6.8448	-0.5136
967	5e+12	NDD	7.145	6.8066	-0.3384
1204	1e+13	NDD	7.3753	6.965	-0.4103
1284	1e+13	NDD	7.2948	6.959	-0.3358
1292	5e+12	NDD	7.3654	7.0005	-0.3649
1364	1e+13	NDD	7.1172	6.86	-0.2572
1383	5e+12	NDD	7.4561	6.8377	-0.6184
1388	5e+12	NDD	7.2375	6.8196	-0.4179
1427	1e+13	NDD	7.4549	6.8001	-0.6548
1666	0	CORRELATION	7.1085	6.7674	-0.3411

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	7.1085	7.325	7.4326	0.1466	6.7674	6.8593	6.9664	0.082748	-0.5969	-0.46567	-0.3411	0.11438
1e+12	7.1128	7.2887	7.4452	0.14471	6.7816	6.8483	6.9645	0.081812	-0.5136	-0.4404	-0.3105	0.089676
5e+12	7.145	7.301	7.4561	0.13732	6.8066	6.8661	7.0005	0.090503	-0.6184	-0.4349	-0.3384	0.12672
1e+13	7.1172	7.3106	7.4549	0.14452	6.8001	6.896	6.965	0.080048	-0.6548	-0.41453	-0.2572	0.17195

Device Test: 24.21 TIMING|OUT_RISE/OUTH/5.5/12/0/1000/5.5/500kHz//@OUT_RISE_LDO





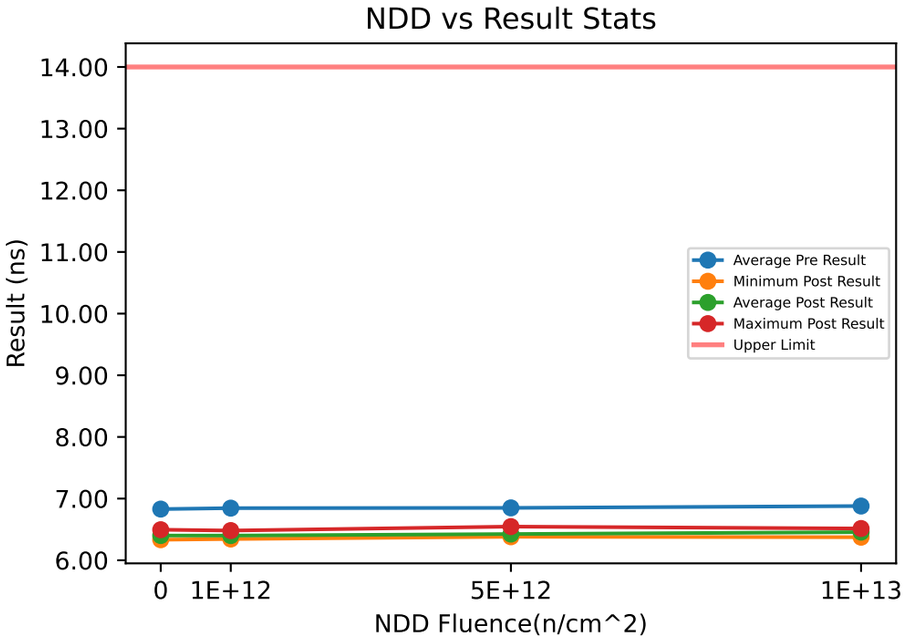
Test Results (Upper Limit = 16.0 (ns))

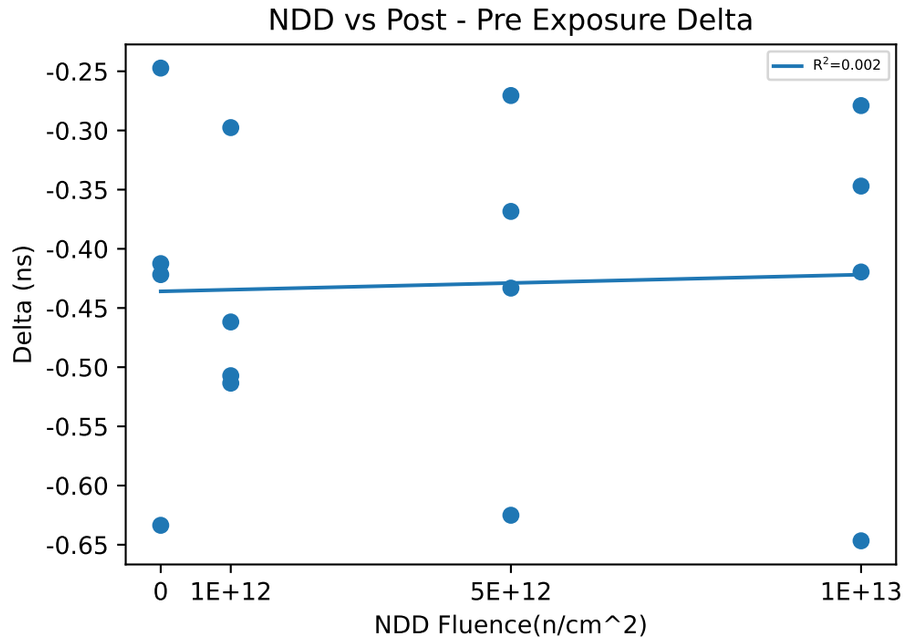
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	8.448	8.299	-0.149
466	1e+12	NDD	8.4029	7.9871	-0.4158
762	0	CORRELATION	8.6467	8.1808	-0.4659
769	1e+12	NDD	8.1953	7.958	-0.2373
887	1e+12	NDD	8.7117	8.5083	-0.2034
891	0	CORRELATION	8.6718	8.4445	-0.2273
927	1e+12	NDD	8.681	8.1782	-0.5028
967	5e+12	NDD	8.1241	7.9613	-0.1628
1204	1e+13	NDD	8.6753	8.471	-0.2043
1284	1e+13	NDD	8.4125	8.5997	0.1872
1292	5e+12	NDD	8.6778	8.6153	-0.0625
1364	1e+13	NDD	8.2389	8.2336	-0.0053
1383	5e+12	NDD	8.7244	8.1884	-0.536
1388	5e+12	NDD	8.4284	8.1406	-0.2878
1427	1e+13	NDD	8.6594	8.0045	-0.6549
1666	0	CORRELATION	8.1588	7.968	-0.1908

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.1588	8.4813	8.6718	0.23718	7.968	8.2231	8.4445	0.20137	-0.4659	-0.25825	-0.149	0.14208
1e+12	8.1953	8.4977	8.7117	0.24483	7.958	8.1579	8.5083	0.2532	-0.5028	-0.33982	-0.2034	0.14313
5e+12	8.1241	8.4887	8.7244	0.27561	7.9613	8.2264	8.6153	0.27708	-0.536	-0.26228	-0.0625	0.20444
1e+13	8.2389	8.4965	8.6753	0.2097	8.0045	8.3272	8.5997	0.26321	-0.6549	-0.16932	0.1872	0.36103

Device Test: 24.22 TIMING|OUT_FALL/OUTH/5.5/12/0/1000/5.5/500kHz//@OUT_FALL_LDO





Test Results (Upper Limit = 14.0 (ns))

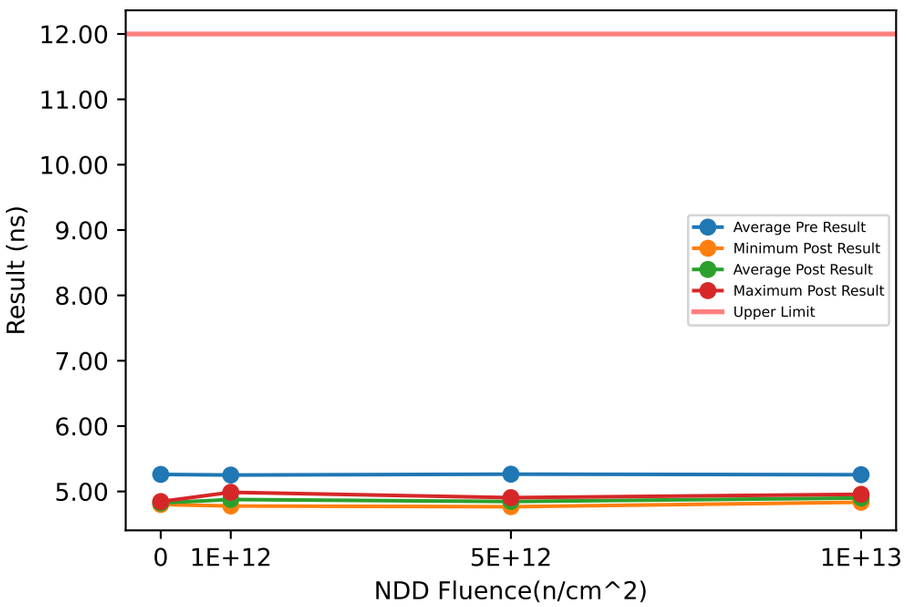
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	6.8303	6.4085	-0.4218
466	1e+12	NDD	6.8062	6.3444	-0.4618
762	0	CORRELATION	7.0006	6.367	-0.6336
769	1e+12	NDD	6.6813	6.3837	-0.2976
887	1e+12	NDD	6.9949	6.4814	-0.5135
891	0	CORRELATION	6.9077	6.4952	-0.4125
927	1e+12	NDD	6.8978	6.3906	-0.5072
967	5e+12	NDD	6.6606	6.3901	-0.2705
1204	1e+13	NDD	6.9343	6.5147	-0.4196
1284	1e+13	NDD	6.8586	6.5116	-0.347
1292	5e+12	NDD	6.9141	6.5457	-0.3684
1364	1e+13	NDD	6.7028	6.4238	-0.279
1383	5e+12	NDD	7.0082	6.3831	-0.6251
1388	5e+12	NDD	6.814	6.3808	-0.4332
1427	1e+13	NDD	7.0204	6.3737	-0.6467
1666	0	CORRELATION	6.5802	6.3329	-0.2473

Test Statistics (ns)

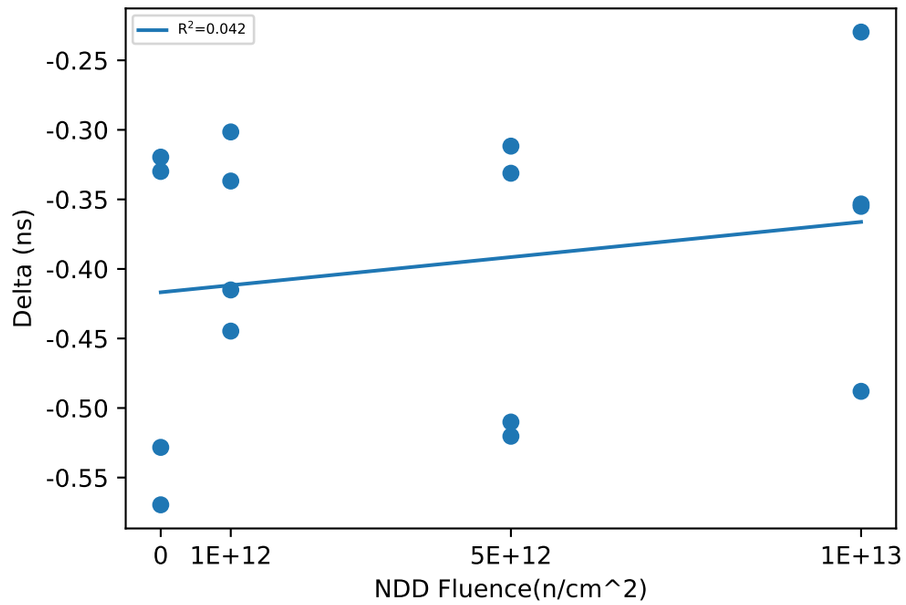
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	6.5802	6.8297	7.0006	0.18032	6.3329	6.4009	6.4952	0.070056	-0.6336	-0.4288	-0.2473	0.15832
1e+12	6.6813	6.8451	6.9949	0.13362	6.3444	6.4	6.4814	0.057941	-0.5135	-0.44503	-0.2976	0.10095
5e+12	6.6606	6.8492	7.0082	0.14866	6.3808	6.4249	6.5457	0.080614	-0.6251	-0.4243	-0.2705	0.14964
1e+13	6.7028	6.879	7.0204	0.1348	6.3737	6.4559	6.5147	0.069155	-0.6467	-0.42308	-0.279	0.15976

Device Test: 24.23 TIMING|OUT_RISE/OUTH/4.5/12/0/220/4.5/500kHz//@OUT_RISE_220PF

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 12.0 (ns))

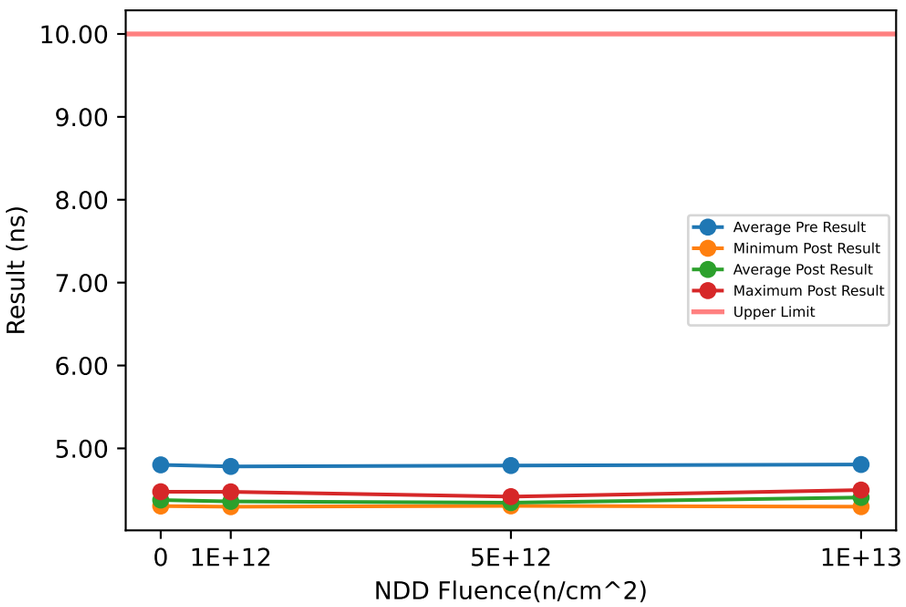
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	5.3283	4.8	-0.5283
466	1e+12	NDD	5.3134	4.8687	-0.4447
762	0	CORRELATION	5.3822	4.8126	-0.5696
769	1e+12	NDD	5.1745	4.873	-0.3015
887	1e+12	NDD	5.3238	4.987	-0.3368
891	0	CORRELATION	5.165	4.8454	-0.3196
927	1e+12	NDD	5.1925	4.7774	-0.4151
967	5e+12	NDD	5.2168	4.9051	-0.3117
1204	1e+13	NDD	5.1412	4.9115	-0.2297
1284	1e+13	NDD	5.3093	4.956	-0.3533
1292	5e+12	NDD	5.2189	4.8877	-0.3312
1364	1e+13	NDD	5.1897	4.8347	-0.355
1383	5e+12	NDD	5.3351	4.825	-0.5101
1388	5e+12	NDD	5.2867	4.7664	-0.5203
1427	1e+13	NDD	5.3848	4.8968	-0.488
1666	0	CORRELATION	5.1681	4.8382	-0.3299

Test Statistics (ns)

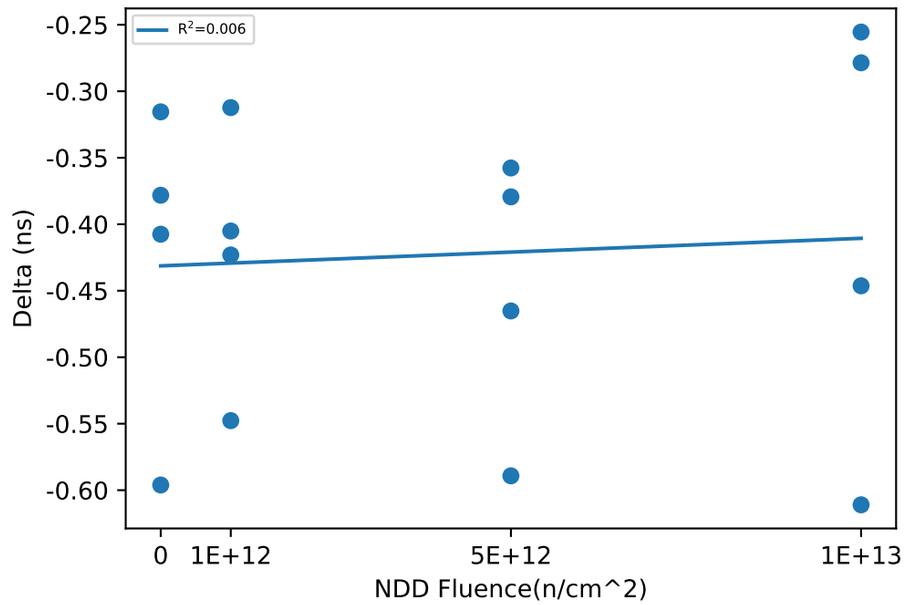
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	5.165	5.2609	5.3822	0.11115	4.8	4.824	4.8454	0.021335	-0.5696	-0.43685	-0.3196	0.1306
1e+12	5.1745	5.2511	5.3238	0.07846	4.7774	4.8765	4.987	0.085837	-0.4447	-0.37452	-0.3015	0.06665
5e+12	5.2168	5.2644	5.3351	0.057247	4.7664	4.846	4.9051	0.063269	-0.5203	-0.41832	-0.3117	0.11222
1e+13	5.1412	5.2563	5.3848	0.11106	4.8347	4.8998	4.956	0.050141	-0.488	-0.3565	-0.2297	0.10549

Device Test: 24.24 TIMING|OUT_FALL/OUTH/4.5/12/0/220/4.5/500kHz//@OUT_FALL_220PF

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 10.0 (ns))

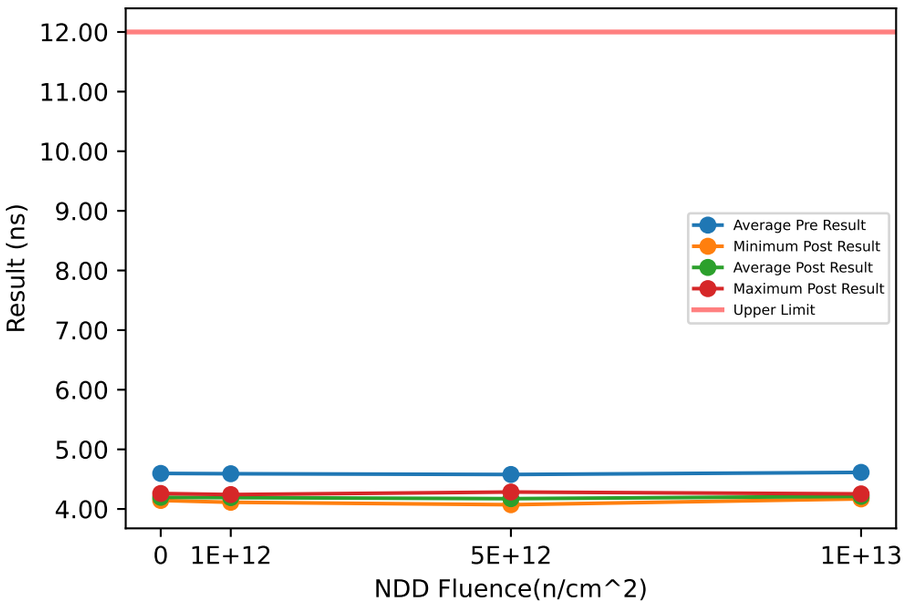
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.8159	4.4084	-0.4075
466	1e+12	NDD	4.7214	4.3163	-0.4051
762	0	CORRELATION	4.9004	4.3043	-0.5961
769	1e+12	NDD	4.6085	4.2962	-0.3123
887	1e+12	NDD	4.8989	4.4758	-0.4231
891	0	CORRELATION	4.855	4.4768	-0.3782
927	1e+12	NDD	4.8995	4.3518	-0.5477
967	5e+12	NDD	4.7077	4.35	-0.3577
1204	1e+13	NDD	4.8966	4.4503	-0.4463
1284	1e+13	NDD	4.7529	4.4974	-0.2555
1292	5e+12	NDD	4.8831	4.4179	-0.4652
1364	1e+13	NDD	4.6649	4.3863	-0.2786
1383	5e+12	NDD	4.8956	4.3064	-0.5892
1388	5e+12	NDD	4.6854	4.306	-0.3794
1427	1e+13	NDD	4.9078	4.2968	-0.611
1666	0	CORRELATION	4.6333	4.3178	-0.3155

Test Statistics (ns)

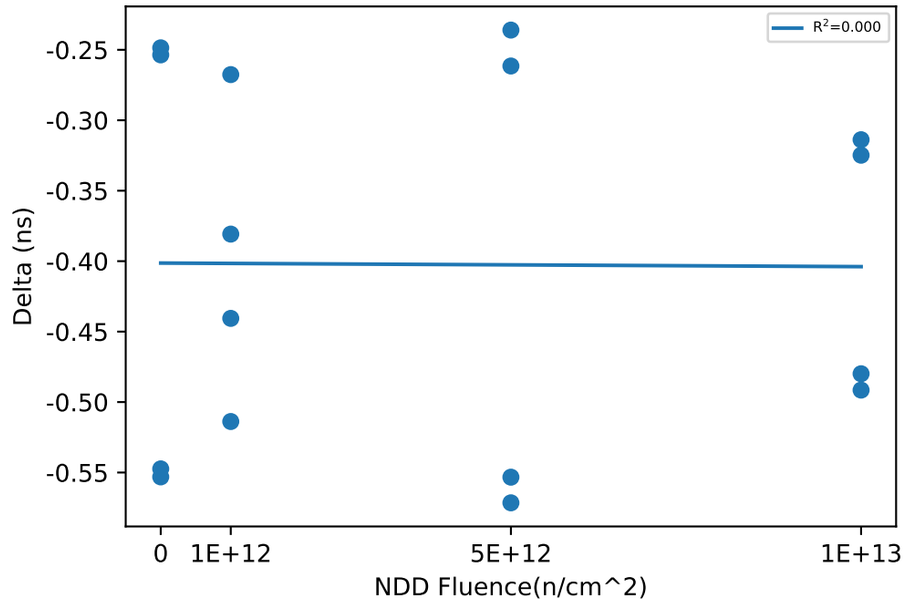
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6333	4.8011	4.9004	0.11711	4.3043	4.3768	4.4768	0.081109	-0.5961	-0.42433	-0.3155	0.12078
1e+12	4.6085	4.7821	4.8995	0.14288	4.2962	4.36	4.4758	0.080534	-0.5477	-0.42205	-0.3123	0.096818
5e+12	4.6854	4.7929	4.8956	0.1118	4.306	4.3451	4.4179	0.052758	-0.5892	-0.44787	-0.3577	0.10503
1e+13	4.6649	4.8056	4.9078	0.11733	4.2968	4.4077	4.4974	0.086829	-0.611	-0.39785	-0.2555	0.16559

Device Test: 24.25 TIMING|OUT_RISE/OUTH/5/12/0/220/5/500kHz//@OUT_RISE_220PF

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



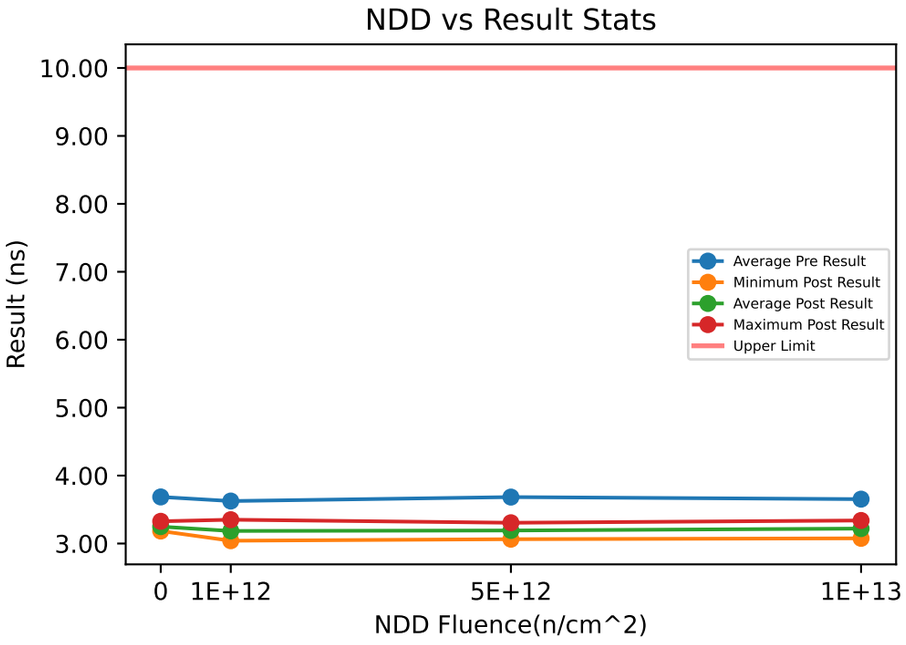
Test Results (Upper Limit = 12.0 (ns))

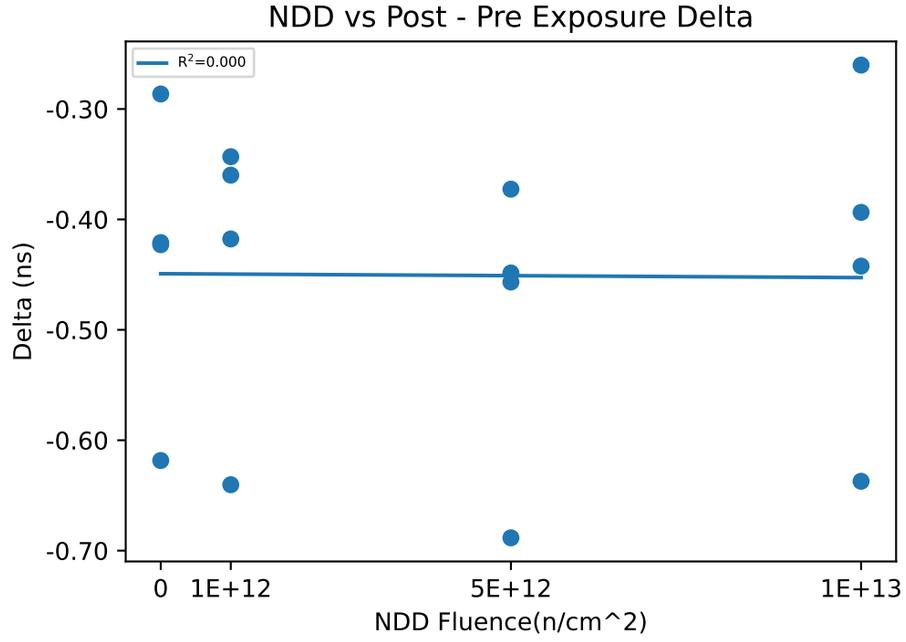
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.7077	4.1546	-0.5531
466	1e+12	NDD	4.6824	4.2418	-0.4406
762	0	CORRELATION	4.6907	4.1433	-0.5474
769	1e+12	NDD	4.4909	4.2233	-0.2676
887	1e+12	NDD	4.6988	4.185	-0.5138
891	0	CORRELATION	4.5134	4.2598	-0.2536
927	1e+12	NDD	4.4932	4.1124	-0.3808
967	5e+12	NDD	4.4861	4.2246	-0.2615
1204	1e+13	NDD	4.5236	4.1988	-0.3248
1284	1e+13	NDD	4.704	4.2241	-0.4799
1292	5e+12	NDD	4.5204	4.2844	-0.236
1364	1e+13	NDD	4.483	4.1692	-0.3138
1383	5e+12	NDD	4.665	4.1117	-0.5533
1388	5e+12	NDD	4.6431	4.0716	-0.5715
1427	1e+13	NDD	4.7448	4.2533	-0.4915
1666	0	CORRELATION	4.4743	4.2257	-0.2486

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.4743	4.5965	4.7077	0.11983	4.1433	4.1959	4.2598	0.056106	-0.5531	-0.40067	-0.2486	0.17274
1e+12	4.4909	4.5913	4.6988	0.11483	4.1124	4.1906	4.2418	0.057264	-0.5138	-0.4007	-0.2676	0.10408
5e+12	4.4861	4.5786	4.665	0.088635	4.0716	4.1731	4.2844	0.098509	-0.5715	-0.40558	-0.236	0.18154
1e+13	4.483	4.6138	4.7448	0.1298	4.1692	4.2114	4.2533	0.035854	-0.4915	-0.4025	-0.3138	0.096293

Device Test: 24.26 TIMING|OUT_FALL/OUTH/5/12/0/220/5/500kHz//@OUT_FALL_220PF





Test Results (Upper Limit = 10.0 (ns))

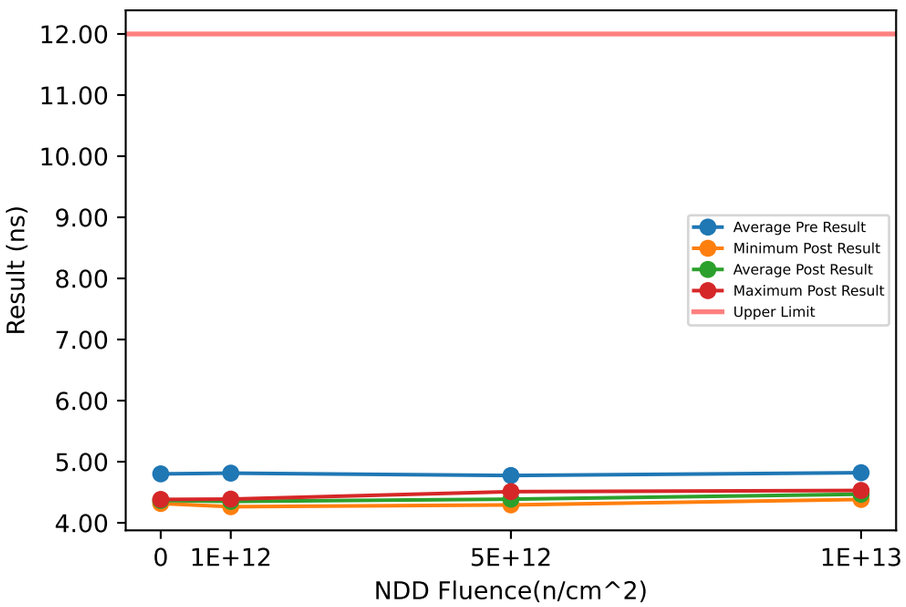
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.6048	3.1838	-0.421
466	1e+12	NDD	3.6369	3.277	-0.3599
762	0	CORRELATION	3.8187	3.2003	-0.6184
769	1e+12	NDD	3.3845	3.0413	-0.3432
887	1e+12	NDD	3.7683	3.3506	-0.4177
891	0	CORRELATION	3.706	3.2831	-0.4229
927	1e+12	NDD	3.7115	3.0712	-0.6403
967	5e+12	NDD	3.4364	3.0638	-0.3726
1204	1e+13	NDD	3.7814	3.3391	-0.4423
1284	1e+13	NDD	3.5688	3.3086	-0.2602
1292	5e+12	NDD	3.7541	3.3056	-0.4485
1364	1e+13	NDD	3.47	3.0764	-0.3936
1383	5e+12	NDD	3.9064	3.218	-0.6884
1388	5e+12	NDD	3.6373	3.1806	-0.4567
1427	1e+13	NDD	3.7927	3.1555	-0.6372
1666	0	CORRELATION	3.6134	3.327	-0.2864

Test Statistics (ns)

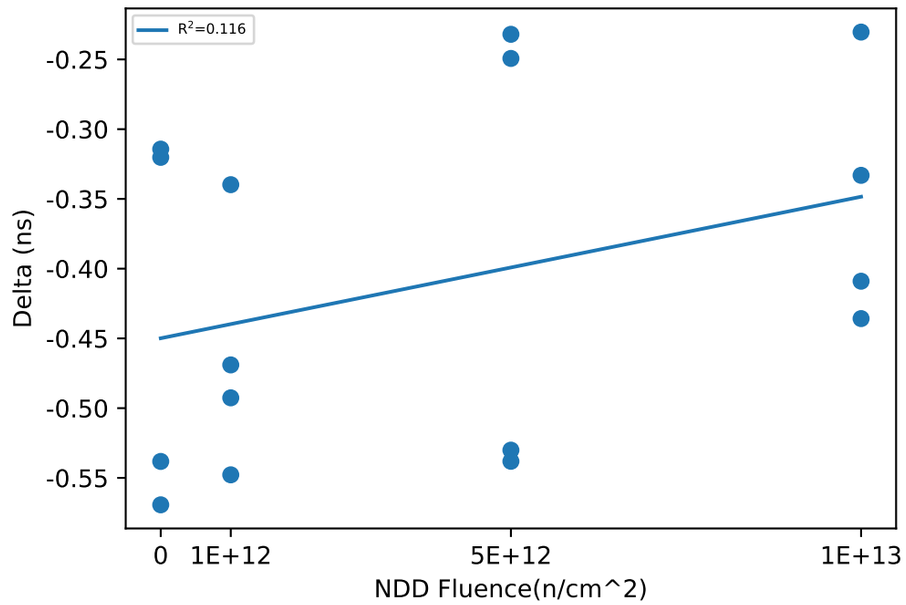
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.6048	3.6857	3.8187	0.099788	3.1838	3.2485	3.327	0.067992	-0.6184	-0.43717	-0.2864	0.13668
1e+12	3.3845	3.6253	3.7683	0.16931	3.0413	3.185	3.3506	0.15219	-0.6403	-0.44027	-0.3432	0.13712
5e+12	3.4364	3.6836	3.9064	0.19821	3.0638	3.192	3.3056	0.10024	-0.6884	-0.49155	-0.3726	0.13659
1e+13	3.47	3.6532	3.7927	0.15977	3.0764	3.2199	3.3391	0.12492	-0.6372	-0.43332	-0.2602	0.1562

Device Test: 24.27 TIMING|OUT_RISE/OUTH/5.5/12/0/220/5.5/500kHz//@OUT_RISE_220PF

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



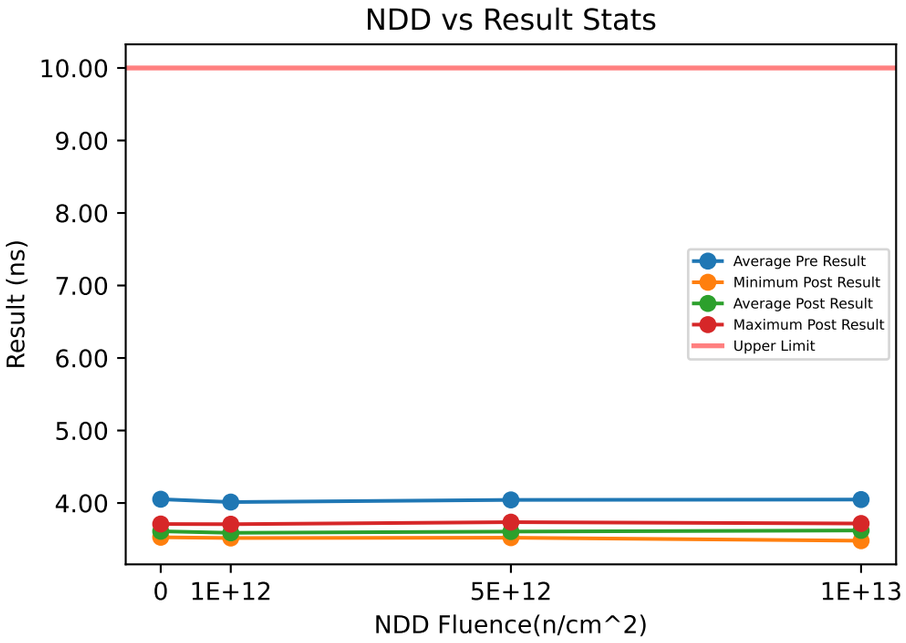
Test Results (Upper Limit = 12.0 (ns))

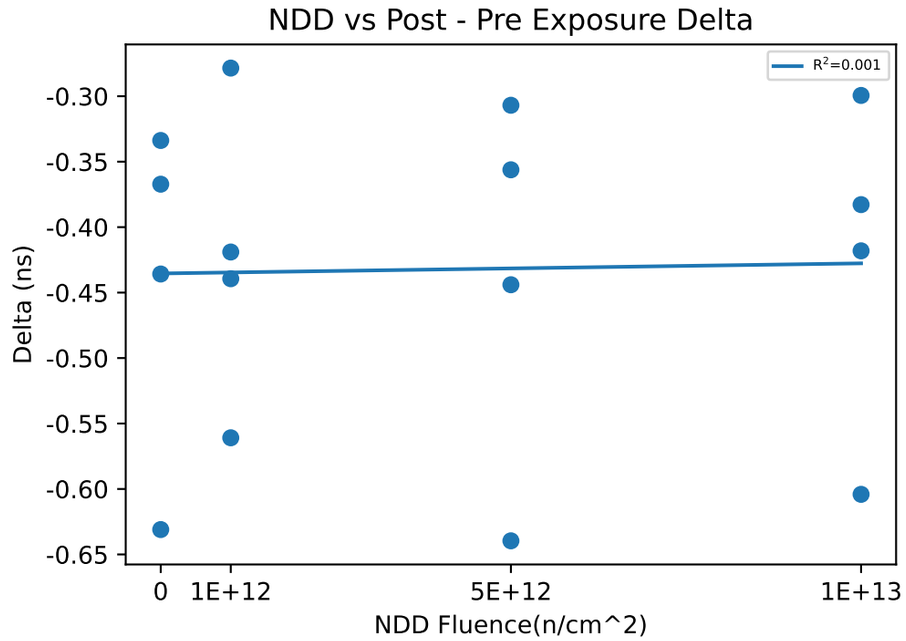
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	4.9204	4.3822	-0.5382
466	1e+12	NDD	4.9361	4.3883	-0.5478
762	0	CORRELATION	4.886	4.3167	-0.5693
769	1e+12	NDD	4.7147	4.3749	-0.3398
887	1e+12	NDD	4.8688	4.3762	-0.4926
891	0	CORRELATION	4.6973	4.383	-0.3143
927	1e+12	NDD	4.7327	4.2637	-0.469
967	5e+12	NDD	4.6772	4.4452	-0.232
1204	1e+13	NDD	4.736	4.5056	-0.2304
1284	1e+13	NDD	4.9387	4.5297	-0.409
1292	5e+12	NDD	4.7597	4.5104	-0.2493
1364	1e+13	NDD	4.7157	4.3826	-0.3331
1383	5e+12	NDD	4.8314	4.2933	-0.5381
1388	5e+12	NDD	4.8297	4.2996	-0.5301
1427	1e+13	NDD	4.8908	4.455	-0.4358
1666	0	CORRELATION	4.7007	4.3805	-0.3202

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	4.6973	4.8011	4.9204	0.11874	4.3167	4.3656	4.383	0.032617	-0.5693	-0.4355	-0.3143	0.13715
1e+12	4.7147	4.8131	4.9361	0.10705	4.2637	4.3508	4.3883	0.058363	-0.5478	-0.4623	-0.3398	0.08809
5e+12	4.6772	4.7745	4.8314	0.072963	4.2933	4.3871	4.5104	0.10806	-0.5381	-0.38738	-0.232	0.1696
1e+13	4.7157	4.8203	4.9387	0.11111	4.3826	4.4682	4.5297	0.06502	-0.4358	-0.35207	-0.2304	0.092042

Device Test: 24.28 TIMING|OUT_FALL/OUTH/5.5/12/0/220/5.5/500kHz//@OUT_FALL_220PF





Test Results (Upper Limit = 10.0 (ns))

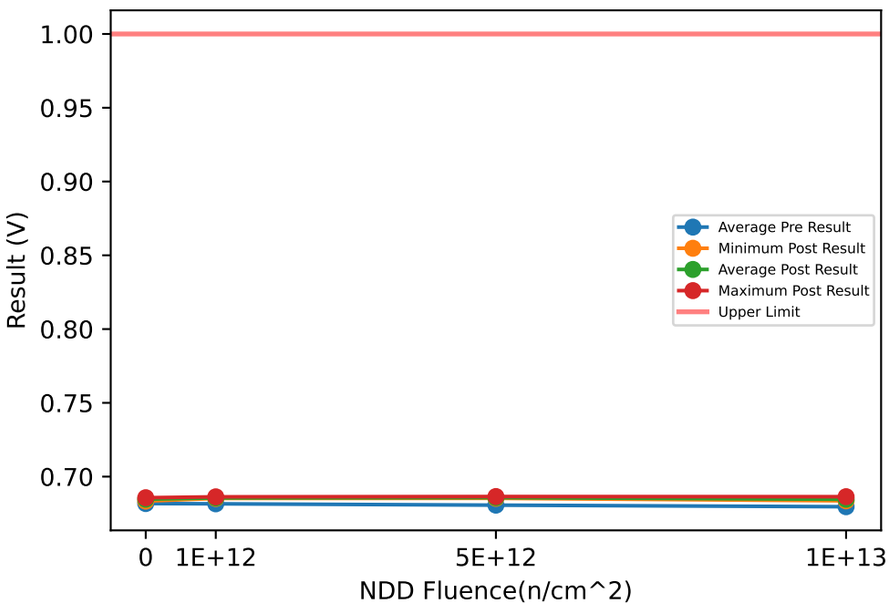
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	3.9634	3.5276	-0.4358
466	1e+12	NDD	4.004	3.585	-0.419
762	0	CORRELATION	4.1958	3.5648	-0.631
769	1e+12	NDD	3.8227	3.5442	-0.2785
887	1e+12	NDD	4.1472	3.7078	-0.4394
891	0	CORRELATION	4.0774	3.7102	-0.3672
927	1e+12	NDD	4.0781	3.5172	-0.5609
967	5e+12	NDD	3.8285	3.5216	-0.3069
1204	1e+13	NDD	4.1352	3.7171	-0.4181
1284	1e+13	NDD	4.0008	3.7014	-0.2994
1292	5e+12	NDD	4.0922	3.736	-0.3562
1364	1e+13	NDD	3.8627	3.4799	-0.3828
1383	5e+12	NDD	4.2234	3.5838	-0.6396
1388	5e+12	NDD	4.0268	3.5828	-0.444
1427	1e+13	NDD	4.1918	3.5877	-0.6041
1666	0	CORRELATION	3.9714	3.6376	-0.3338

Test Statistics (ns)

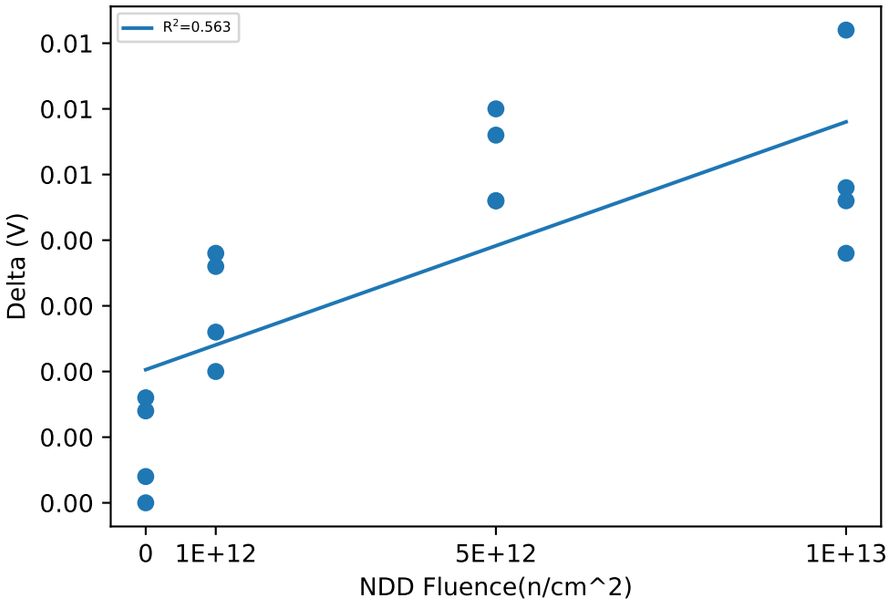
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	3.9634	4.052	4.1958	0.10904	3.5276	3.6101	3.7102	0.0809	-0.631	-0.44195	-0.3338	0.13299
1e+12	3.8227	4.013	4.1472	0.13969	3.5172	3.5886	3.7078	0.084244	-0.5609	-0.42445	-0.2785	0.11572
5e+12	3.8285	4.0427	4.2234	0.16456	3.5216	3.6061	3.736	0.091386	-0.6396	-0.43667	-0.3069	0.14669
1e+13	3.8627	4.0476	4.1918	0.14702	3.4799	3.6215	3.7171	0.11063	-0.6041	-0.4261	-0.2994	0.12868

Device Test: 24.29 VOLTAGE|OUT_CLAMP/OUTL/0/0/0/0/0/0//@OUT_CLAMP_0V

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



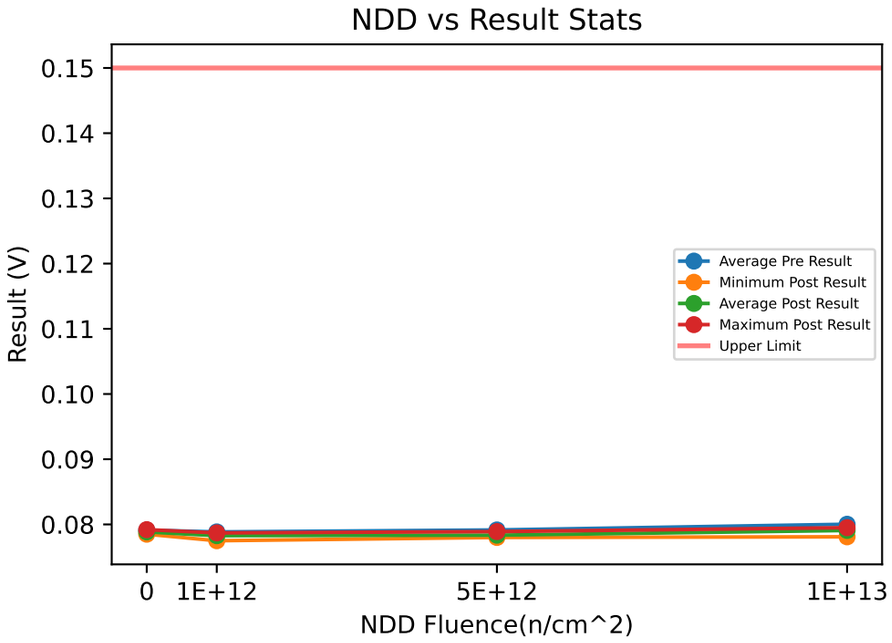
Test Results (Upper Limit = 1.0 (V))

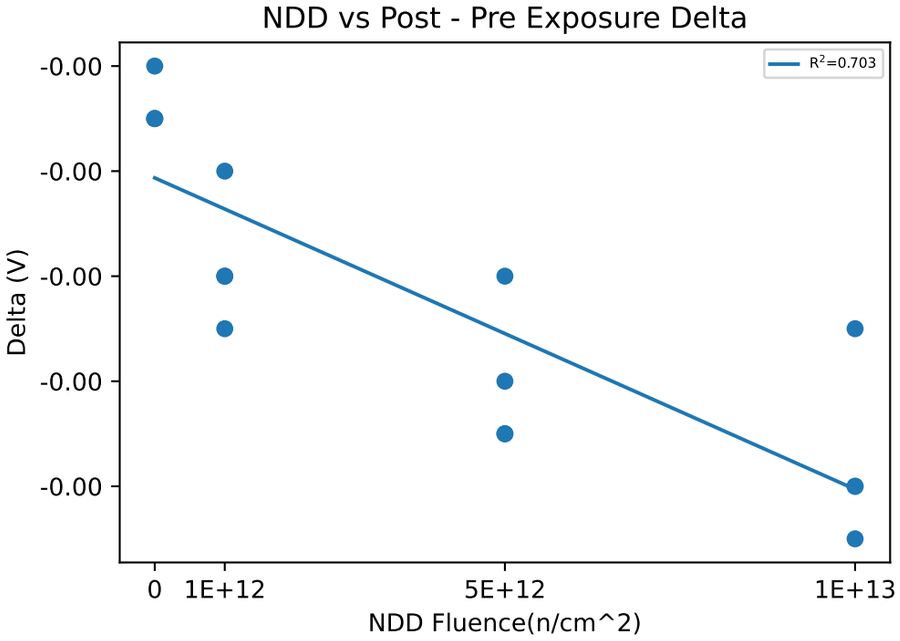
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.6807	0.6834	0.0027
466	1e+12	NDD	0.6808	0.6852	0.0044
762	0	CORRELATION	0.6812	0.6844	0.0032
769	1e+12	NDD	0.682	0.6863	0.0043
887	1e+12	NDD	0.6814	0.6852	0.0038
891	0	CORRELATION	0.6827	0.6852	0.0025
927	1e+12	NDD	0.6821	0.6856	0.0035
967	5e+12	NDD	0.681	0.6865	0.0055
1204	1e+13	NDD	0.6799	0.6847	0.0048
1284	1e+13	NDD	0.6795	0.6839	0.0044
1292	5e+12	NDD	0.6805	0.6853	0.0048
1364	1e+13	NDD	0.6787	0.6836	0.0049
1383	5e+12	NDD	0.6805	0.6858	0.0053
1388	5e+12	NDD	0.6807	0.6855	0.0048
1427	1e+13	NDD	0.6803	0.6864	0.0061
1666	0	CORRELATION	0.6824	0.6857	0.0033

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.6807	0.68175	0.6827	0.00095394	0.6834	0.68468	0.6857	0.0010046	0.0025	0.002925	0.0033	0.00038622
1e+12	0.6808	0.68158	0.6821	0.00060208	0.6852	0.68558	0.6863	0.00051881	0.0035	0.004	0.0044	0.00042426
5e+12	0.6805	0.68068	0.681	0.00023629	0.6853	0.68578	0.6865	0.0005252	0.0048	0.0051	0.0055	0.0003559
1e+13	0.6787	0.6796	0.6803	0.00068313	0.6836	0.68465	0.6864	0.0012557	0.0044	0.00505	0.0061	0.00073258

Device Test: 24.3 LEVEL|LOW_LEVEL/OUTL/5/5/0/0/5/500kHz//@OUT_VOL





Test Results (Upper Limit = 0.15 (V))

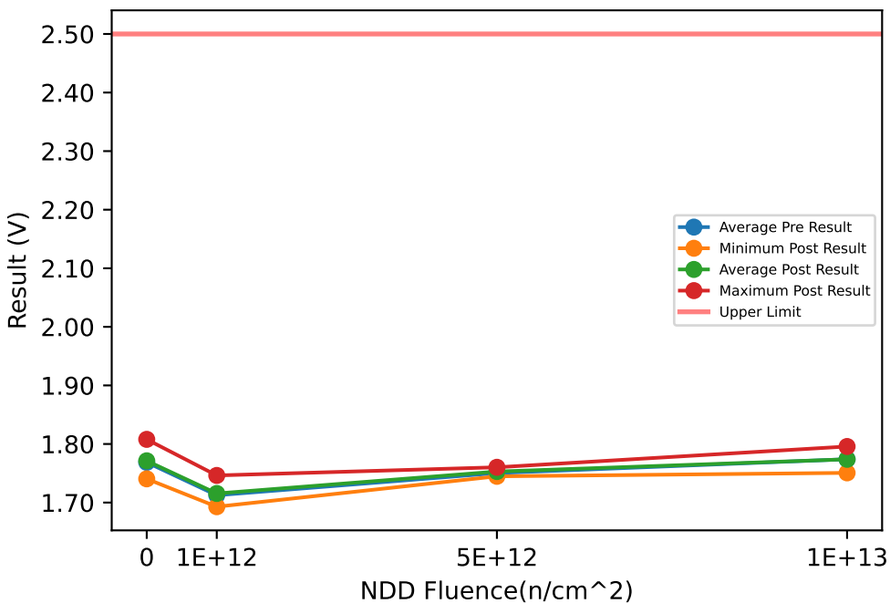
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0793	0.0791	-0.0002
466	1e+12	NDD	0.0781	0.0775	-0.0006
762	0	CORRELATION	0.0795	0.0792	-0.0003
769	1e+12	NDD	0.0792	0.0786	-0.0006
887	1e+12	NDD	0.079	0.0783	-0.0007
891	0	CORRELATION	0.0789	0.0786	-0.0003
927	1e+12	NDD	0.0791	0.0787	-0.0004
967	5e+12	NDD	0.0793	0.0784	-0.0009
1204	1e+13	NDD	0.0804	0.0794	-0.001
1284	1e+13	NDD	0.0804	0.0793	-0.0011
1292	5e+12	NDD	0.0798	0.0789	-0.0009
1364	1e+13	NDD	0.0802	0.0795	-0.0007
1383	5e+12	NDD	0.0787	0.0781	-0.0006
1388	5e+12	NDD	0.0788	0.078	-0.0008
1427	1e+13	NDD	0.0791	0.0781	-0.001
1666	0	CORRELATION	0.0788	0.0785	-0.0003

Test Statistics (V)

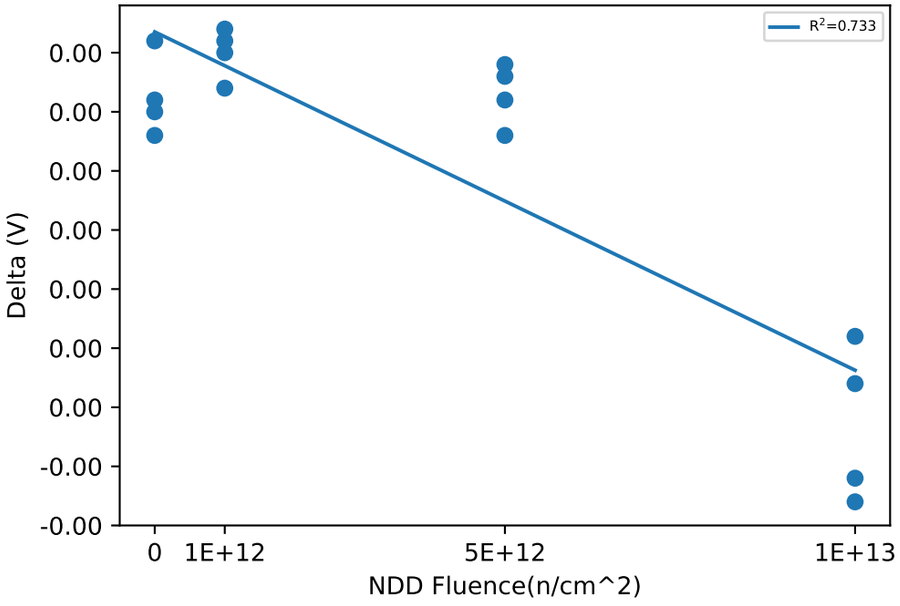
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0788	0.079125	0.0795	0.0003304	0.0785	0.07885	0.0792	0.00035119	-0.0003	-0.000275	-0.0002	5e-05
1e+12	0.0781	0.07885	0.0792	0.00050662	0.0775	0.078275	0.0787	0.00054391	-0.0007	-0.000575	-0.0004	0.00012583
5e+12	0.0787	0.07915	0.0798	0.00050662	0.078	0.07835	0.0789	0.00040415	-0.0009	-0.0008	-0.0006	0.00014142
1e+13	0.0791	0.080025	0.0804	0.00062383	0.0781	0.079075	0.0795	0.00065511	-0.0011	-0.00095	-0.0007	0.00017321

Device Test: 24.30 VOLTAGE|OUT_CLAMP/OUTL/5/0/0/0/0/0//@OUT_CLAMP_FULL

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 2.5 (V))

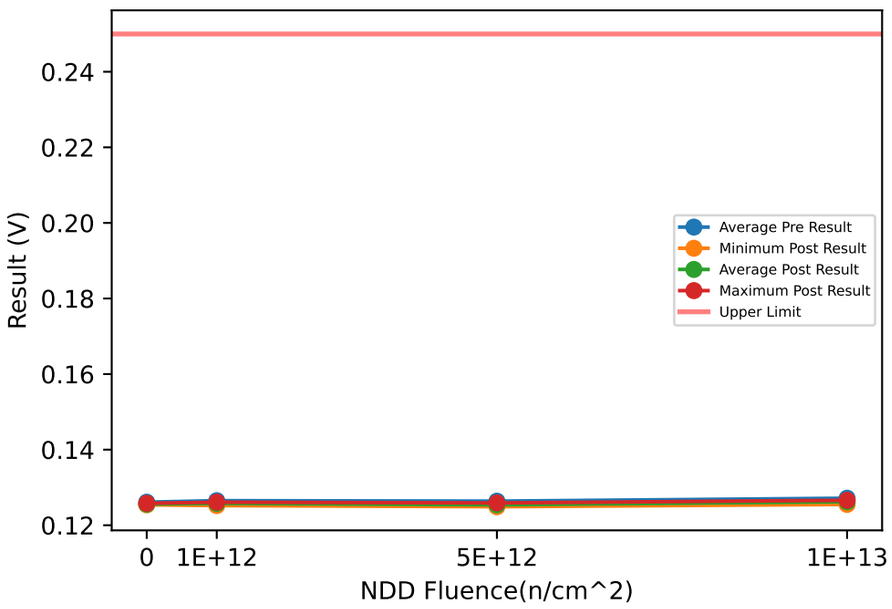
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.7382	1.7405	0.0023
466	1e+12	NDD	1.6899	1.6931	0.0032
762	0	CORRELATION	1.7666	1.7692	0.0026
769	1e+12	NDD	1.7433	1.7463	0.003
887	1e+12	NDD	1.6902	1.6929	0.0027
891	0	CORRELATION	1.8054	1.8079	0.0025
927	1e+12	NDD	1.7266	1.7297	0.0031
967	5e+12	NDD	1.7516	1.7545	0.0029
1204	1e+13	NDD	1.7755	1.7757	0.0002
1284	1e+13	NDD	1.7515	1.7507	-0.0008
1292	5e+12	NDD	1.7422	1.7448	0.0026
1364	1e+13	NDD	1.7739	1.7733	-0.0006
1383	5e+12	NDD	1.7574	1.7602	0.0028
1388	5e+12	NDD	1.75	1.7523	0.0023
1427	1e+13	NDD	1.7951	1.7957	0.0006
1666	0	CORRELATION	1.7645	1.7676	0.0031

Test Statistics (V)

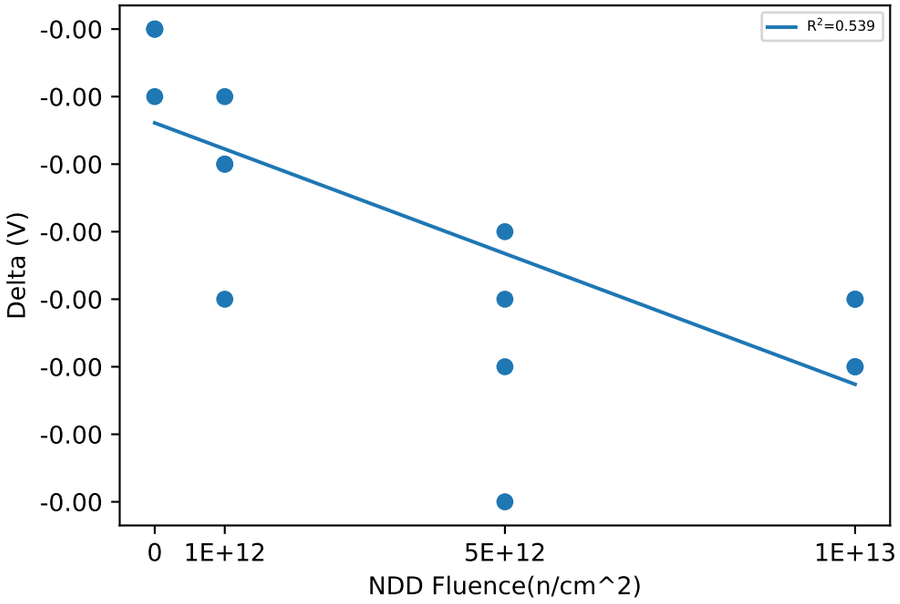
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.7382	1.7687	1.8054	0.027684	1.7405	1.7713	1.8079	0.027727	0.0023	0.002625	0.0031	0.00034034
1e+12	1.6899	1.7125	1.7433	0.026805	1.6929	1.7155	1.7463	0.02685	0.0027	0.003	0.0032	0.00021602
5e+12	1.7422	1.7503	1.7574	0.0062663	1.7448	1.753	1.7602	0.0063721	0.0023	0.00265	0.0029	0.00026458
1e+13	1.7515	1.774	1.7951	0.01783	1.7507	1.7738	1.7957	0.018413	-0.0008	-0.00015	0.0006	0.00066081

Device Test: 24.4 LEVEL|HIGH_LEVEL/OUTH/5/5/0/0/5/500kHz//@OUT_VOH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



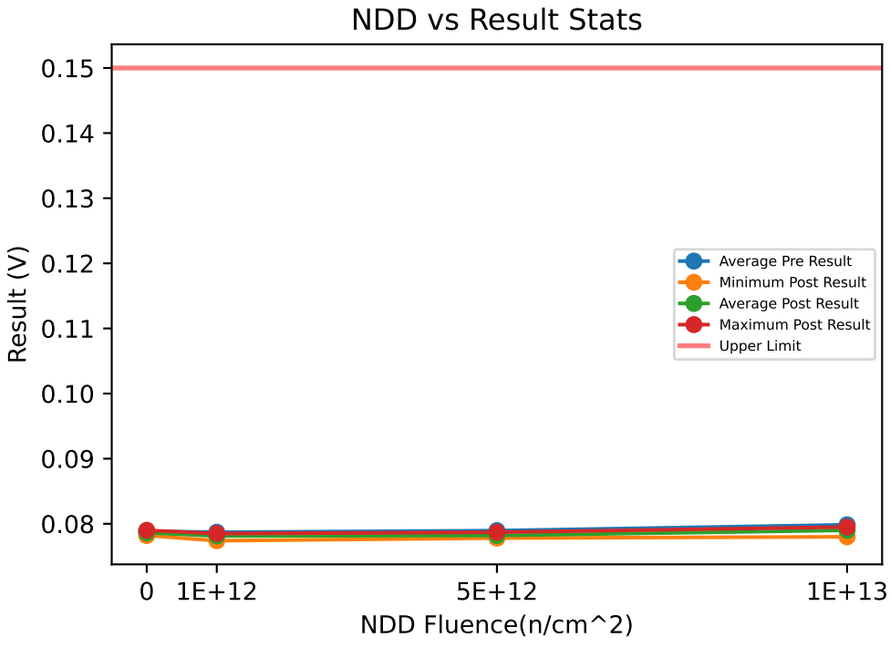
Test Results (Upper Limit = 0.25 (V))

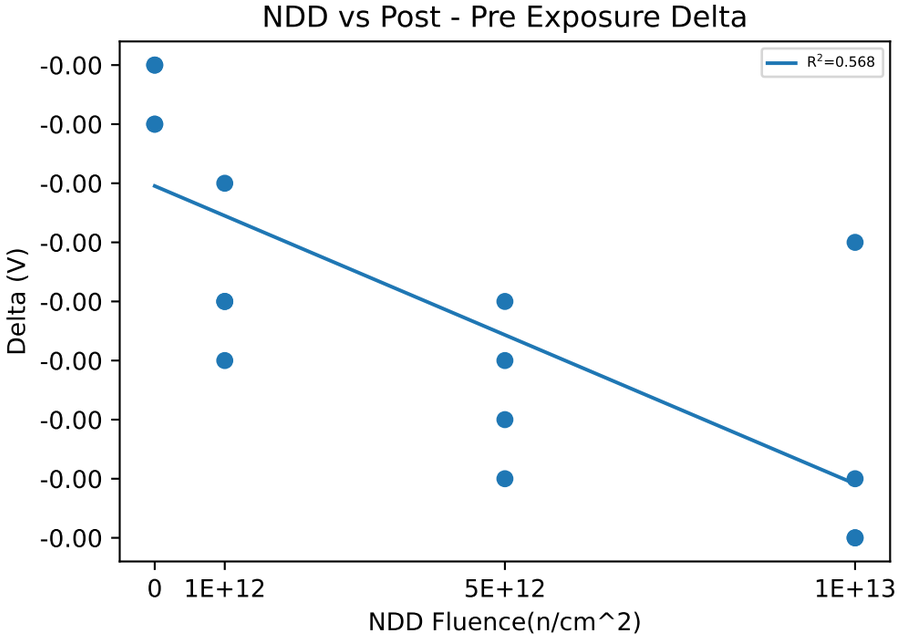
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.1259	0.1254	-0.0005
466	1e+12	NDD	0.1265	0.1258	-0.0007
762	0	CORRELATION	0.1262	0.1256	-0.0006
769	1e+12	NDD	0.1261	0.1252	-0.0009
887	1e+12	NDD	0.1268	0.1261	-0.0007
891	0	CORRELATION	0.126	0.1255	-0.0005
927	1e+12	NDD	0.1266	0.126	-0.0006
967	5e+12	NDD	0.1269	0.1259	-0.001
1204	1e+13	NDD	0.1272	0.1263	-0.0009
1284	1e+13	NDD	0.1274	0.1264	-0.001
1292	5e+12	NDD	0.1267	0.1258	-0.0009
1364	1e+13	NDD	0.1275	0.1266	-0.0009
1383	5e+12	NDD	0.1262	0.125	-0.0012
1388	5e+12	NDD	0.1257	0.1249	-0.0008
1427	1e+13	NDD	0.1265	0.1255	-0.001
1666	0	CORRELATION	0.1263	0.1258	-0.0005

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1259	0.1261	0.1263	0.00018257	0.1254	0.12557	0.1258	0.00017078	-0.0006	-0.000525	-0.0005	5e-05
1e+12	0.1261	0.1265	0.1268	0.00029439	0.1252	0.12577	0.1261	0.00040311	-0.0009	-0.000725	-0.0006	0.00012583
5e+12	0.1257	0.12638	0.1269	0.00053774	0.1249	0.1254	0.1259	0.00052281	-0.0012	-0.000975	-0.0008	0.00017078
1e+13	0.1265	0.12715	0.1275	0.00045092	0.1255	0.1262	0.1266	0.00048305	-0.001	-0.00095	-0.0009	5.7735e-05

Device Test: 24.5 LEVEL|LOW_LEVEL/OUTL/12/12/0/0/5/500kHz//@OUT_VOL





Test Results (Upper Limit = 0.15 (V))

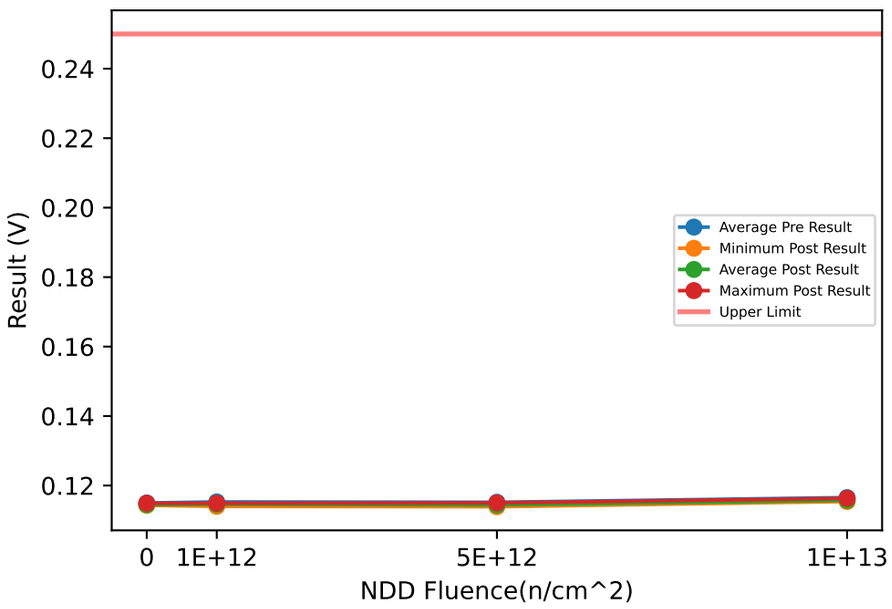
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0792	0.079	-0.0002
466	1e+12	NDD	0.078	0.0774	-0.0006
762	0	CORRELATION	0.0792	0.079	-0.0002
769	1e+12	NDD	0.0791	0.0785	-0.0006
887	1e+12	NDD	0.0788	0.0781	-0.0007
891	0	CORRELATION	0.0786	0.0783	-0.0003
927	1e+12	NDD	0.0789	0.0785	-0.0004
967	5e+12	NDD	0.0791	0.0783	-0.0008
1204	1e+13	NDD	0.0803	0.0793	-0.001
1284	1e+13	NDD	0.0802	0.0792	-0.001
1292	5e+12	NDD	0.0796	0.0787	-0.0009
1364	1e+13	NDD	0.08	0.0795	-0.0005
1383	5e+12	NDD	0.0786	0.078	-0.0006
1388	5e+12	NDD	0.0785	0.0778	-0.0007
1427	1e+13	NDD	0.0789	0.078	-0.0009
1666	0	CORRELATION	0.0785	0.0782	-0.0003

Test Statistics (V)

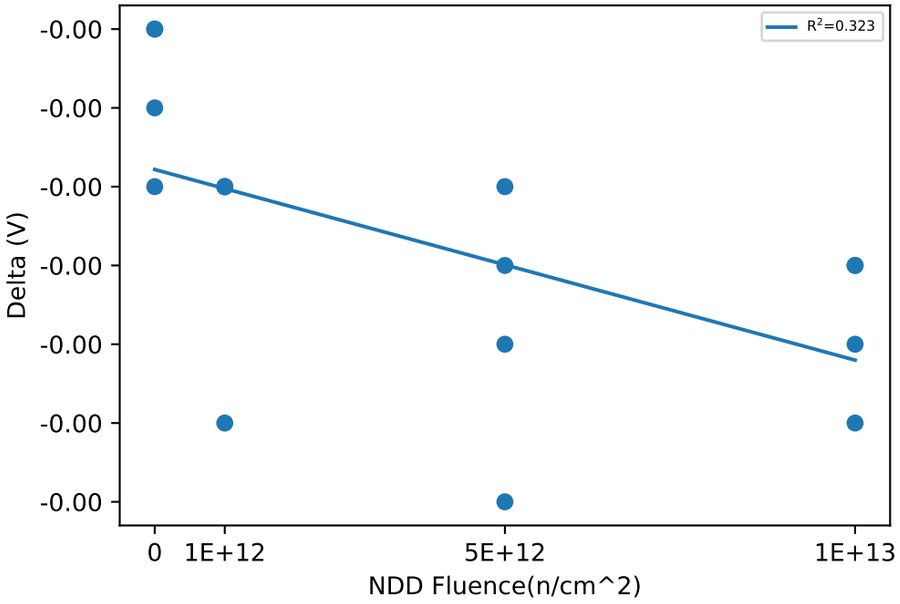
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0785	0.078875	0.0792	0.00037749	0.0782	0.078625	0.079	0.00043493	-0.0003	-0.00025	-0.0002	5.7735e-05
1e+12	0.078	0.0787	0.0791	0.00048305	0.0774	0.078125	0.0785	0.00051881	-0.0007	-0.000575	-0.0004	0.00012583
5e+12	0.0785	0.07895	0.0796	0.00050662	0.0778	0.0782	0.0787	0.00039158	-0.0009	-0.00075	-0.0006	0.0001291
1e+13	0.0789	0.07985	0.0803	0.0006455	0.078	0.079	0.0795	0.00067823	-0.001	-0.00085	-0.0005	0.00023805

Device Test: 24.6 LEVEL|HIGH_LEVEL/OUTH/12/12/0/0/5/500kHz//@OUT_VOH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



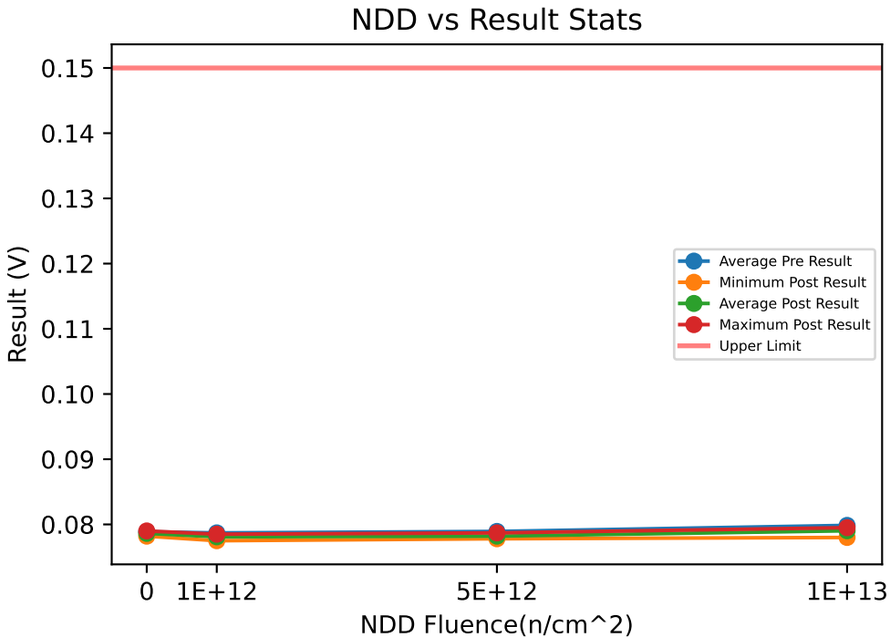
Test Results (Upper Limit = 0.25 (V))

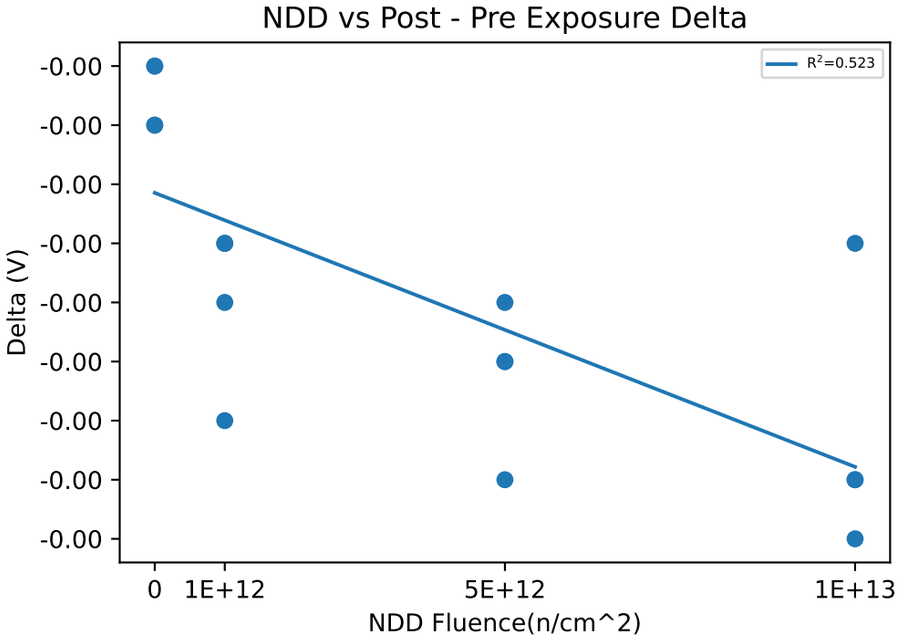
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.1149	0.1143	-0.0006
466	1e+12	NDD	0.1153	0.1147	-0.0006
762	0	CORRELATION	0.1148	0.1143	-0.0005
769	1e+12	NDD	0.1149	0.114	-0.0009
887	1e+12	NDD	0.1155	0.1149	-0.0006
891	0	CORRELATION	0.1149	0.1145	-0.0004
927	1e+12	NDD	0.1154	0.1148	-0.0006
967	5e+12	NDD	0.1154	0.1147	-0.0007
1204	1e+13	NDD	0.1162	0.1155	-0.0007
1284	1e+13	NDD	0.1171	0.1163	-0.0008
1292	5e+12	NDD	0.1158	0.115	-0.0008
1364	1e+13	NDD	0.1163	0.1154	-0.0009
1383	5e+12	NDD	0.1149	0.1139	-0.001
1388	5e+12	NDD	0.1146	0.114	-0.0006
1427	1e+13	NDD	0.1165	0.1158	-0.0007
1666	0	CORRELATION	0.1153	0.1149	-0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1148	0.11497	0.1153	0.00022174	0.1143	0.1145	0.1149	0.00028284	-0.0006	-0.000475	-0.0004	9.5743e-05
1e+12	0.1149	0.11528	0.1155	0.000263	0.114	0.1146	0.1149	0.00040825	-0.0009	-0.000675	-0.0006	0.00015
5e+12	0.1146	0.11517	0.1158	0.00053151	0.1139	0.1144	0.115	0.00053541	-0.001	-0.000775	-0.0006	0.00017078
1e+13	0.1162	0.11653	0.1171	0.00040311	0.1154	0.11575	0.1163	0.00040415	-0.0009	-0.000775	-0.0007	9.5743e-05

Device Test: 24.7 LEVEL|LOW_LEVEL/OUTL/14/14/0/0/5/500kHz//@OUT_VOL





Test Results (Upper Limit = 0.15 (V))

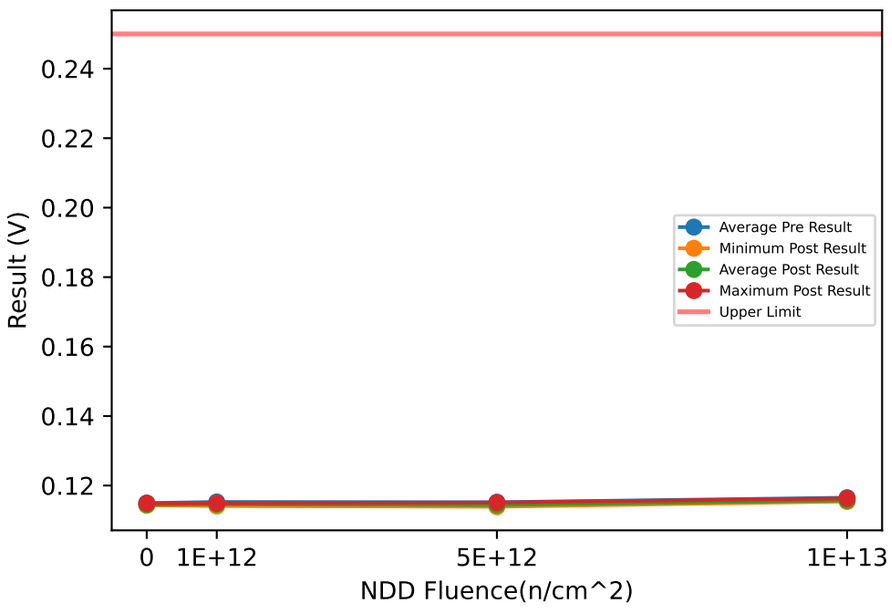
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.0792	0.079	-0.0002
466	1e+12	NDD	0.078	0.0775	-0.0005
762	0	CORRELATION	0.0792	0.0789	-0.0003
769	1e+12	NDD	0.0791	0.0785	-0.0006
887	1e+12	NDD	0.0788	0.078	-0.0008
891	0	CORRELATION	0.0786	0.0784	-0.0002
927	1e+12	NDD	0.0789	0.0784	-0.0005
967	5e+12	NDD	0.079	0.0783	-0.0007
1204	1e+13	NDD	0.0803	0.0794	-0.0009
1284	1e+13	NDD	0.0802	0.0792	-0.001
1292	5e+12	NDD	0.0796	0.0787	-0.0009
1364	1e+13	NDD	0.08	0.0795	-0.0005
1383	5e+12	NDD	0.0786	0.078	-0.0006
1388	5e+12	NDD	0.0785	0.0778	-0.0007
1427	1e+13	NDD	0.0789	0.078	-0.0009
1666	0	CORRELATION	0.0785	0.0782	-0.0003

Test Statistics (V)

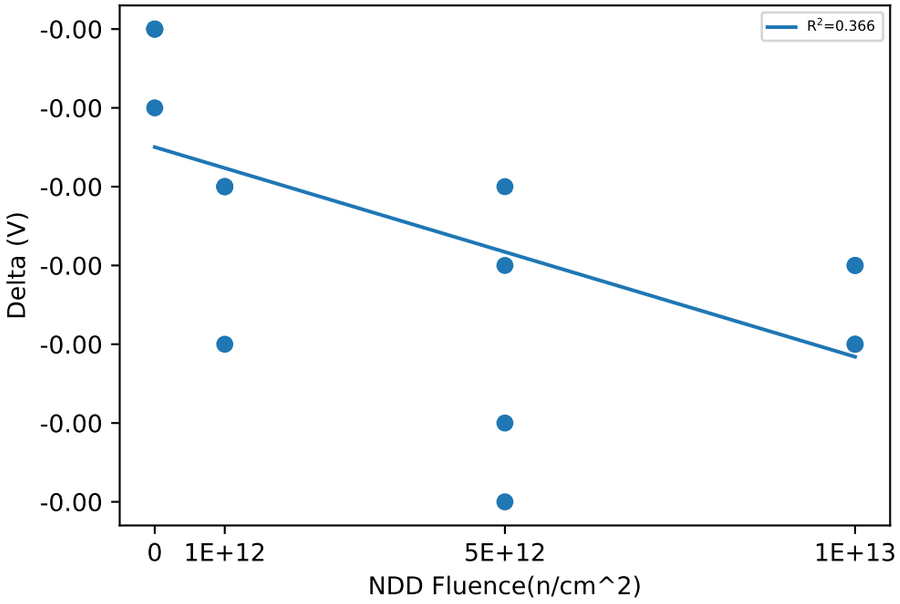
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.0785	0.078875	0.0792	0.00037749	0.0782	0.078625	0.079	0.00038622	-0.0003	-0.00025	-0.0002	5.7735e-05
1e+12	0.078	0.0787	0.0791	0.00048305	0.0775	0.0781	0.0785	0.00045461	-0.0008	-0.0006	-0.0005	0.00014142
5e+12	0.0785	0.078925	0.0796	0.00049917	0.0778	0.0782	0.0787	0.00039158	-0.0009	-0.000725	-0.0006	0.00012583
1e+13	0.0789	0.07985	0.0803	0.0006455	0.078	0.079025	0.0795	0.00069462	-0.001	-0.000825	-0.0005	0.00022174

Device Test: 24.8 LEVEL|HIGH_LEVEL/OUTH/14/14/0/0/5/500kHz//@OUT_VOH

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



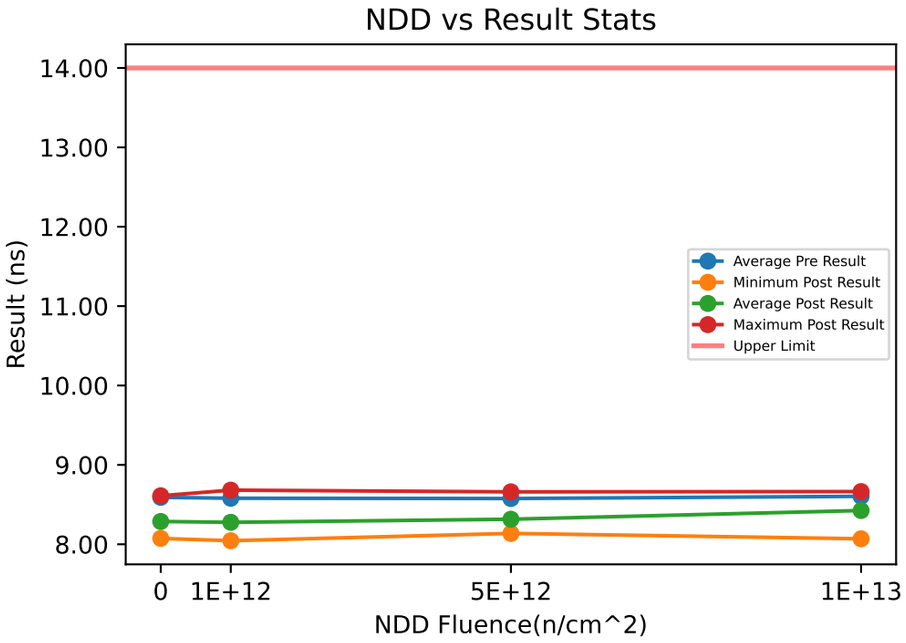
Test Results (Upper Limit = 0.25 (V))

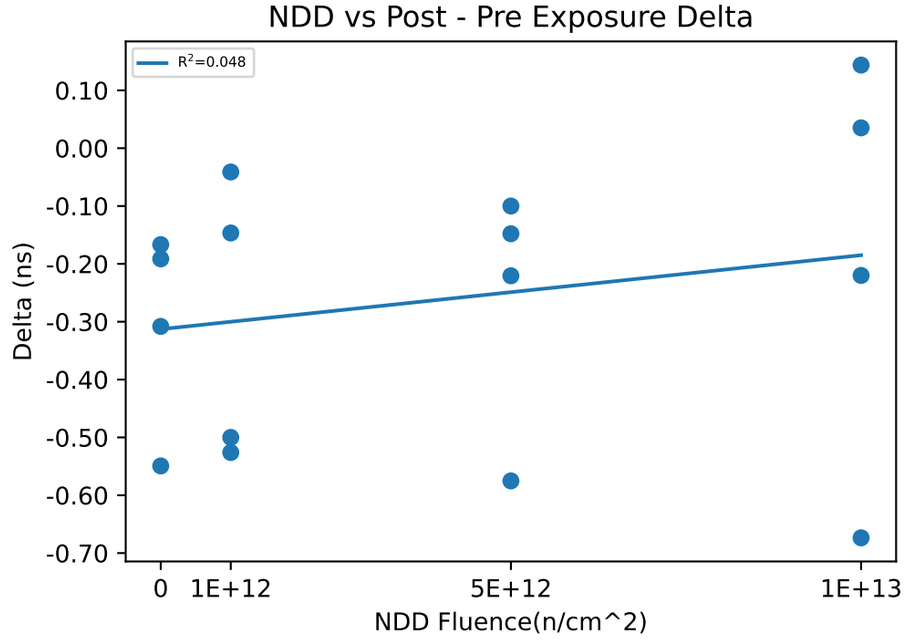
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.1148	0.1144	-0.0004
466	1e+12	NDD	0.1153	0.1147	-0.0006
762	0	CORRELATION	0.1148	0.1143	-0.0005
769	1e+12	NDD	0.1149	0.1141	-0.0008
887	1e+12	NDD	0.1155	0.1149	-0.0006
891	0	CORRELATION	0.1149	0.1145	-0.0004
927	1e+12	NDD	0.1154	0.1148	-0.0006
967	5e+12	NDD	0.1155	0.1146	-0.0009
1204	1e+13	NDD	0.1162	0.1155	-0.0007
1284	1e+13	NDD	0.1171	0.1163	-0.0008
1292	5e+12	NDD	0.1158	0.1151	-0.0007
1364	1e+13	NDD	0.1162	0.1154	-0.0008
1383	5e+12	NDD	0.1149	0.1139	-0.001
1388	5e+12	NDD	0.1146	0.114	-0.0006
1427	1e+13	NDD	0.1165	0.1158	-0.0007
1666	0	CORRELATION	0.1153	0.1149	-0.0004

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.1148	0.11495	0.1153	0.00023805	0.1143	0.11453	0.1149	0.000263	-0.0005	-0.000425	-0.0004	5e-05
1e+12	0.1149	0.11528	0.1155	0.000263	0.1141	0.11463	0.1149	0.0003594	-0.0008	-0.00065	-0.0006	0.0001
5e+12	0.1146	0.1152	0.1158	0.00054772	0.1139	0.1144	0.1151	0.00055976	-0.001	-0.0008	-0.0006	0.00018257
1e+13	0.1162	0.1165	0.1171	0.00042426	0.1154	0.11575	0.1163	0.00040415	-0.0008	-0.00075	-0.0007	5.7735e-05

Device Test: 24.9 TIMING|OUT_RISE/OUTH/4.5/4.5/0/1000/4.5/500kHz//@OUT_RISE_4P5





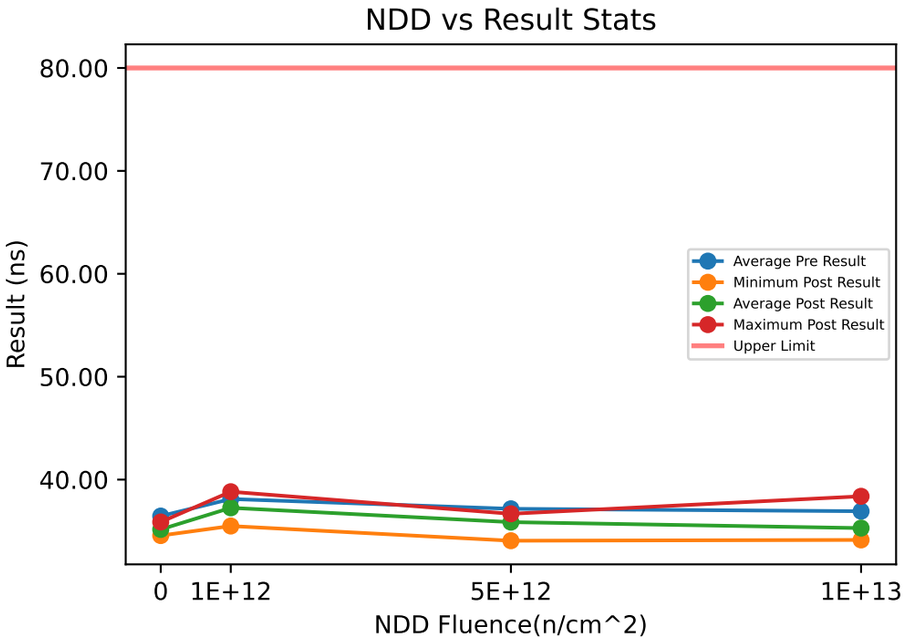
Test Results (Upper Limit = 14.0 (ns))

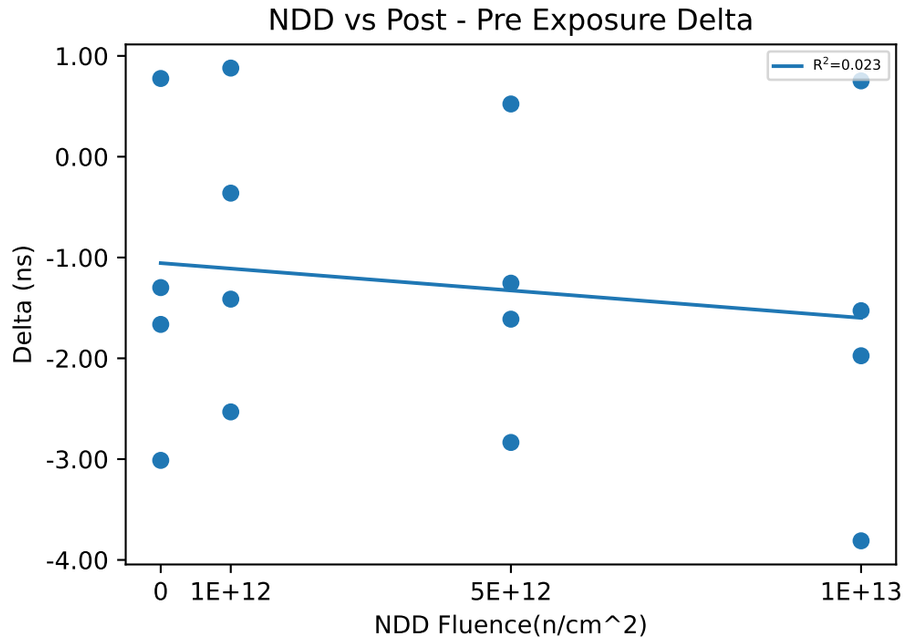
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	8.5178	8.2097	-0.3081
466	1e+12	NDD	8.5448	8.0448	-0.5
762	0	CORRELATION	8.8036	8.2543	-0.5493
769	1e+12	NDD	8.2566	8.11	-0.1466
887	1e+12	NDD	8.7229	8.6818	-0.0411
891	0	CORRELATION	8.8023	8.611	-0.1913
927	1e+12	NDD	8.7954	8.2693	-0.5261
967	5e+12	NDD	8.2371	8.1371	-0.1
1204	1e+13	NDD	8.8577	8.6377	-0.22
1284	1e+13	NDD	8.5202	8.6639	0.1437
1292	5e+12	NDD	8.8083	8.6604	-0.1479
1364	1e+13	NDD	8.2944	8.3296	0.0352
1383	5e+12	NDD	8.8046	8.2294	-0.5752
1388	5e+12	NDD	8.4561	8.2355	-0.2206
1427	1e+13	NDD	8.7429	8.0693	-0.6736
1666	0	CORRELATION	8.2409	8.0742	-0.1667

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	8.2409	8.5911	8.8036	0.26943	8.0742	8.2873	8.611	0.22899	-0.5493	-0.30385	-0.1667	0.17487
1e+12	8.2566	8.5799	8.7954	0.23989	8.0448	8.2765	8.6818	0.2862	-0.5261	-0.30345	-0.0411	0.24606
5e+12	8.2371	8.5765	8.8083	0.28015	8.1371	8.3156	8.6604	0.23423	-0.5752	-0.26092	-0.1	0.2153
1e+13	8.2944	8.6038	8.8577	0.24935	8.0693	8.4251	8.6639	0.28163	-0.6736	-0.17868	0.1437	0.36347

Device Test: 25.1 TIMING|LEB/EN/5/5/0/0/5/500kHz//@T_LEB





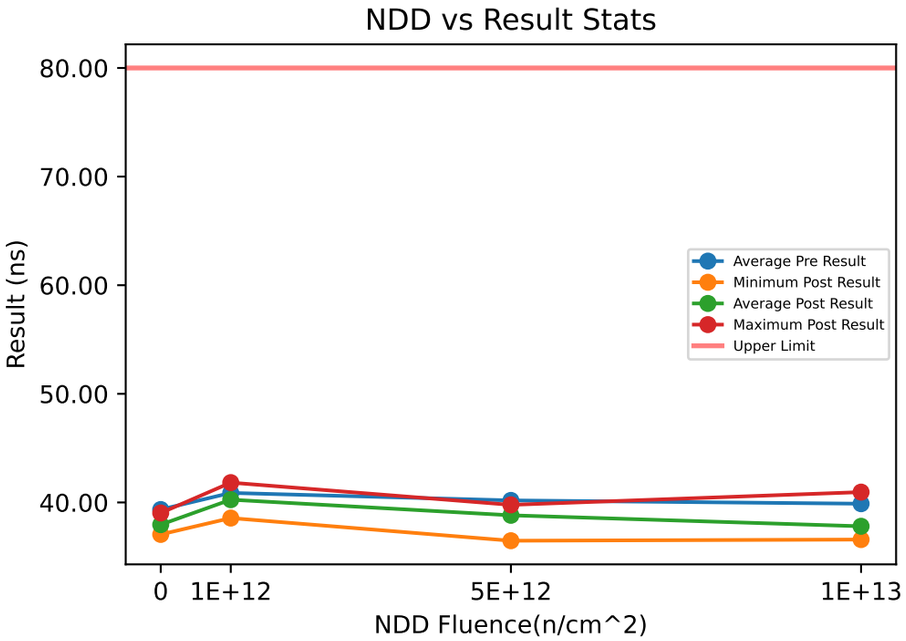
Test Results (Upper Limit = 80.0 (ns))

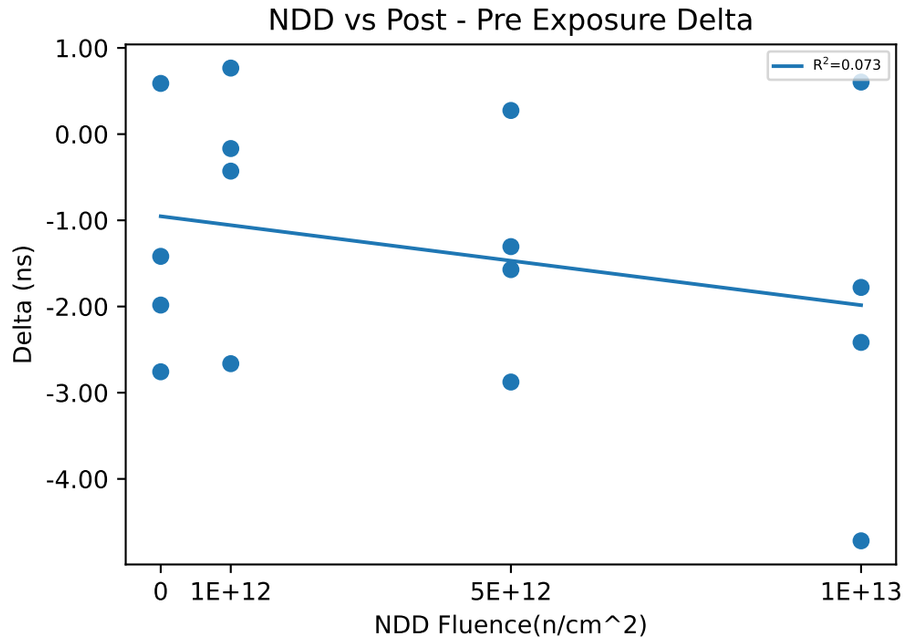
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	38.893	35.88	-3.0124
466	1e+12	NDD	37.772	37.411	-0.3615
762	0	CORRELATION	36.637	34.974	-1.6637
769	1e+12	NDD	37.944	38.823	0.8791
887	1e+12	NDD	39.838	37.307	-2.5317
891	0	CORRELATION	35.862	34.563	-1.2985
927	1e+12	NDD	36.903	35.489	-1.413
967	5e+12	NDD	36.156	36.678	0.5229
1204	1e+13	NDD	35.666	34.139	-1.5276
1284	1e+13	NDD	38.214	34.404	-3.8105
1292	5e+12	NDD	35.316	34.062	-1.2547
1364	1e+13	NDD	36.208	34.233	-1.9748
1383	5e+12	NDD	37.725	36.114	-1.6117
1388	5e+12	NDD	39.454	36.619	-2.8347
1427	1e+13	NDD	37.626	38.378	0.752
1666	0	CORRELATION	34.438	35.214	0.7758

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	34.438	36.458	38.893	1.8615	34.563	35.158	35.88	0.55157	-3.0124	-1.2997	0.7758	1.5678
1e+12	36.903	38.114	39.838	1.2365	35.489	37.258	38.823	1.3667	-2.5317	-0.85678	0.8791	1.4575
5e+12	35.316	37.163	39.454	1.8247	34.062	35.868	36.678	1.2307	-2.8347	-1.2945	0.5229	1.3877
1e+13	35.666	36.929	38.214	1.1906	34.139	35.288	38.378	2.0627	-3.8105	-1.6402	0.752	1.8759

Device Test: 25.4 TIMING|LEB/EN/12/12/0/0/5/500kHz//@T_LEB





Test Results (Upper Limit = 80.0 (ns))

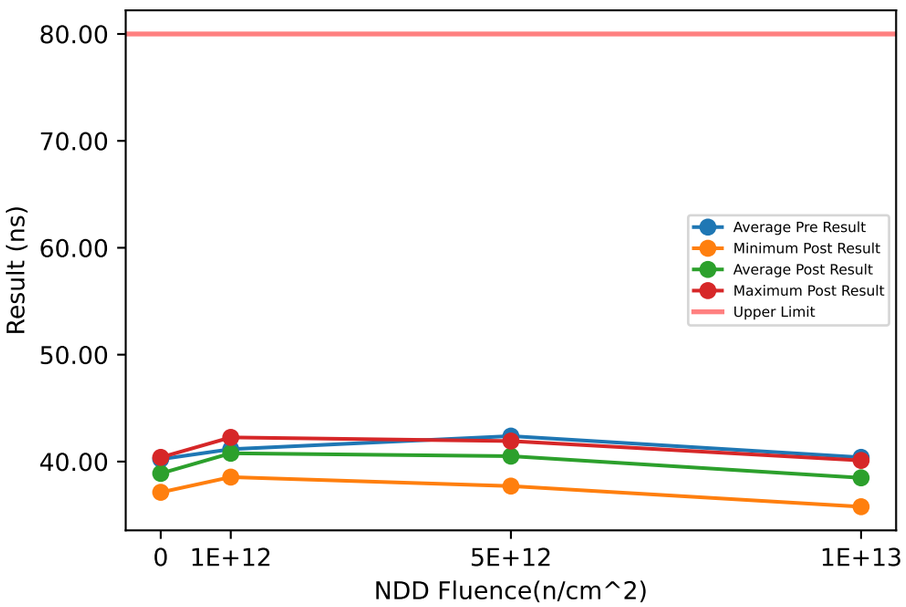
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	41.787	39.03	-2.7573
466	1e+12	NDD	40.931	40.502	-0.4292
762	0	CORRELATION	40.106	38.122	-1.9832
769	1e+12	NDD	41.059	41.826	0.7663
887	1e+12	NDD	42.791	40.128	-2.6632
891	0	CORRELATION	38.474	37.056	-1.4181
927	1e+12	NDD	38.729	38.562	-0.1673
967	5e+12	NDD	39.504	39.779	0.2744
1204	1e+13	NDD	38.361	36.583	-1.7785
1284	1e+13	NDD	41.438	36.719	-4.7184
1292	5e+12	NDD	37.782	36.476	-1.3052
1364	1e+13	NDD	39.388	36.972	-2.4162
1383	5e+12	NDD	40.808	39.236	-1.5719
1388	5e+12	NDD	42.653	39.777	-2.8762
1427	1e+13	NDD	40.347	40.951	0.6039
1666	0	CORRELATION	37.027	37.615	0.5883

Test Statistics (ns)

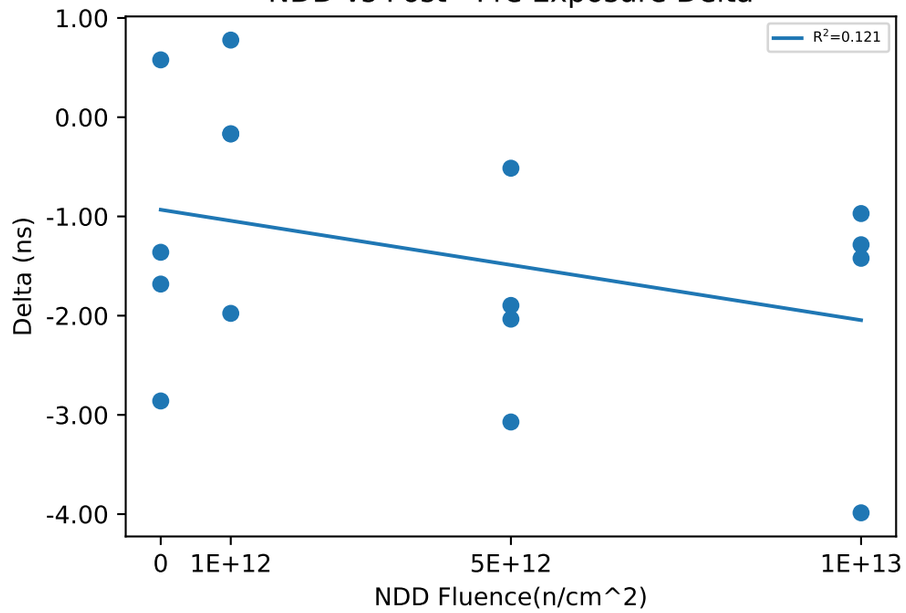
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	37.027	39.348	41.787	2.0554	37.056	37.956	39.03	0.83794	-2.7573	-1.3926	0.5883	1.4301
1e+12	38.729	40.878	42.791	1.6647	38.562	40.254	41.826	1.343	-2.6632	-0.62335	0.7663	1.4535
5e+12	37.782	40.187	42.653	2.0591	36.476	38.817	39.779	1.5812	-2.8762	-1.3697	0.2744	1.2933
1e+13	38.361	39.884	41.438	1.3158	36.583	37.806	40.951	2.1029	-4.7184	-2.0773	0.6039	2.1885

Device Test: 25.7 TIMING|LEB/EN/14/14/0/0/5/500kHz//@T_LEB

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 80.0 (ns))

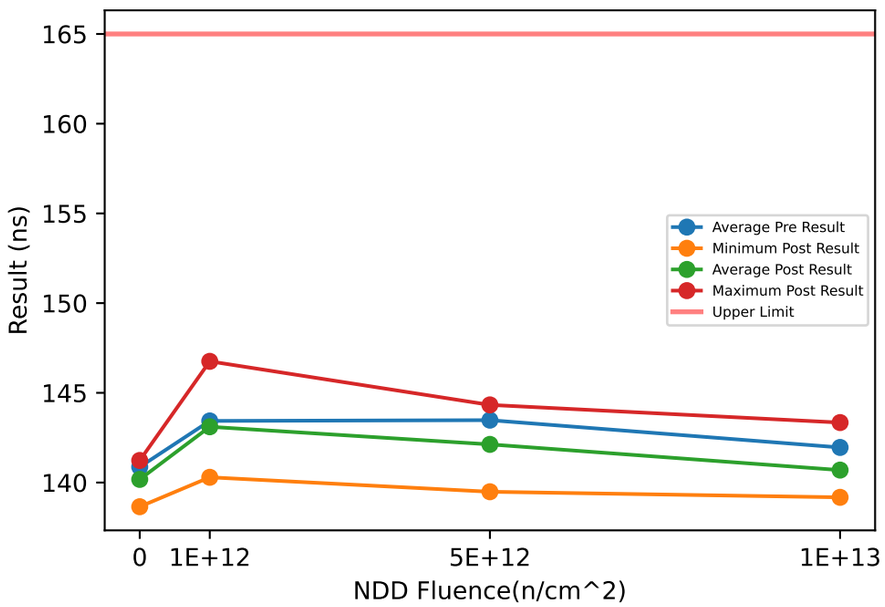
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	39.984	37.124	-2.8597
466	1e+12	NDD	40.661	40.494	-0.1671
762	0	CORRELATION	42.074	40.392	-1.6816
769	1e+12	NDD	41.484	42.261	0.7772
887	1e+12	NDD	43.776	41.799	-1.977
891	0	CORRELATION	39.839	38.477	-1.3613
927	1e+12	NDD	38.716	38.547	-0.1687
967	5e+12	NDD	41.44	40.926	-0.5141
1204	1e+13	NDD	41.527	40.105	-1.4219
1284	1e+13	NDD	39.763	35.776	-3.9869
1292	5e+12	NDD	43.954	41.919	-2.035
1364	1e+13	NDD	40.087	38.801	-1.2853
1383	5e+12	NDD	43.365	41.468	-1.8969
1388	5e+12	NDD	40.778	37.706	-3.0716
1427	1e+13	NDD	40.2	39.229	-0.971
1666	0	CORRELATION	38.993	39.571	0.5778

Test Statistics (ns)

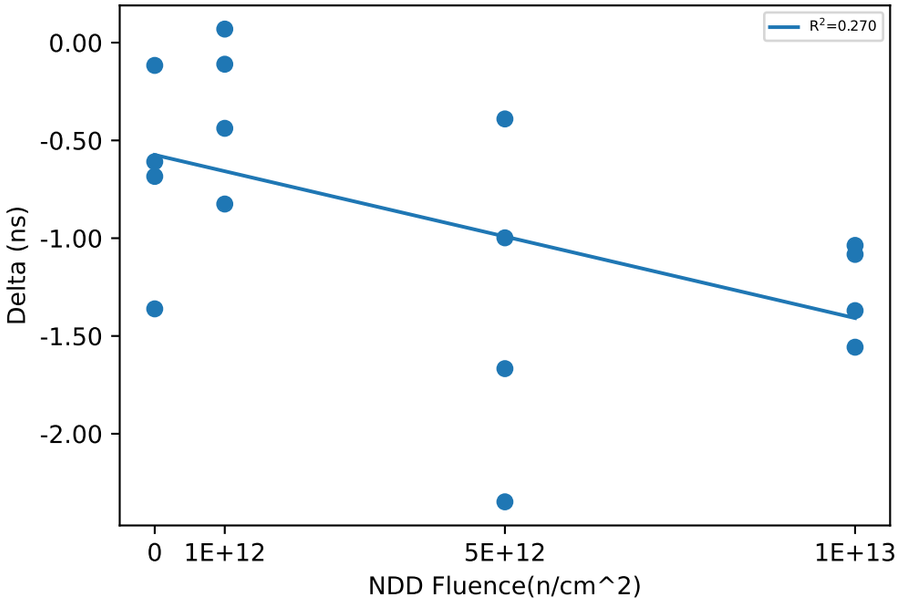
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	38.993	40.222	42.074	1.3093	37.124	38.891	40.392	1.4154	-2.8597	-1.3312	0.5778	1.4265
1e+12	38.716	41.159	43.776	2.0953	38.547	40.775	42.261	1.6634	-1.977	-0.3839	0.7772	1.1517
5e+12	40.778	42.384	43.954	1.5165	37.706	40.505	41.919	1.9095	-3.0716	-1.8794	-0.5141	1.0504
1e+13	39.763	40.394	41.527	0.7776	35.776	38.478	40.105	1.8811	-3.9869	-1.9163	-0.971	1.3933

Device Test: 26.1 TIMING|MIN/OUT/4.5/4.5/0/0/4.5/500kHz//@TON_MIN

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 165.0 (ns))

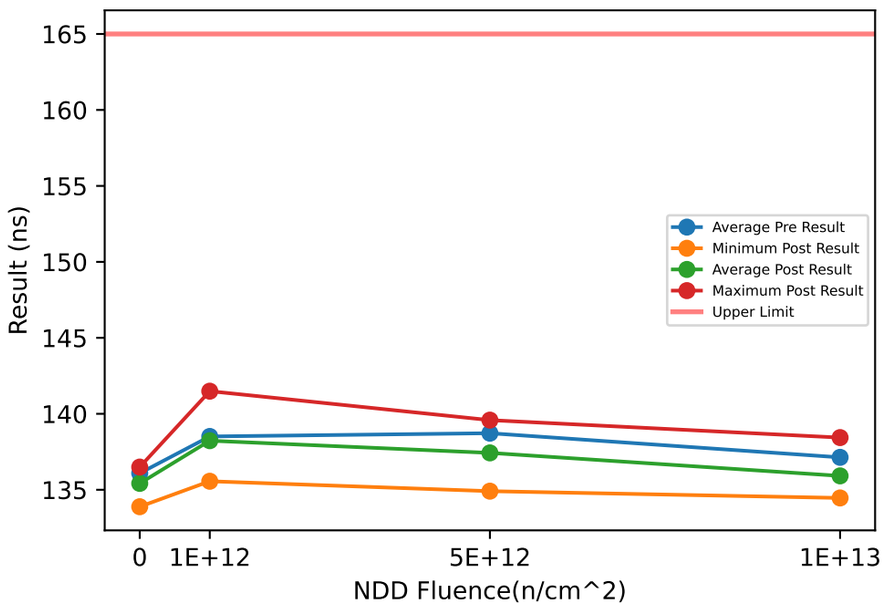
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	140.01	138.65	-1.3613
466	1e+12	NDD	141.74	141.63	-0.1104
762	0	CORRELATION	141.44	140.76	-0.6841
769	1e+12	NDD	143.68	143.75	0.0693
887	1e+12	NDD	147.19	146.75	-0.4382
891	0	CORRELATION	141.84	141.23	-0.6088
927	1e+12	NDD	141.12	140.29	-0.8253
967	5e+12	NDD	142.02	141.63	-0.3902
1204	1e+13	NDD	144.43	143.34	-1.0829
1284	1e+13	NDD	141.26	139.7	-1.5574
1292	5e+12	NDD	145.99	144.33	-1.667
1364	1e+13	NDD	141.92	140.55	-1.3704
1383	5e+12	NDD	144.05	143.06	-0.9981
1388	5e+12	NDD	141.83	139.49	-2.348
1427	1e+13	NDD	140.21	139.18	-1.0369
1666	0	CORRELATION	140.17	140.06	-0.1165

Test Statistics (ns)

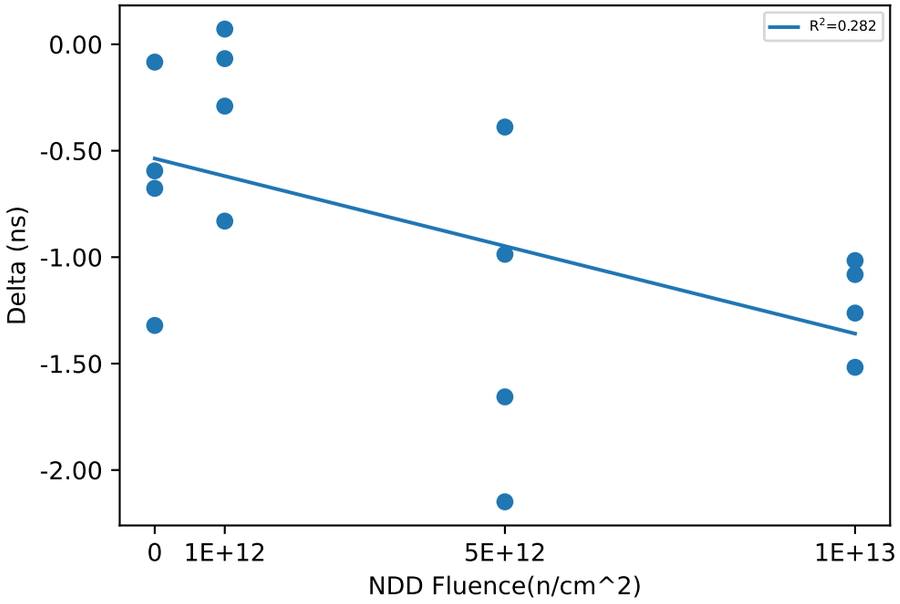
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	140.01	140.87	141.84	0.91039	138.65	140.18	141.23	1.1238	-1.3613	-0.69268	-0.1165	0.51191
1e+12	141.12	143.43	147.19	2.733	140.29	143.11	146.75	2.8172	-0.8253	-0.32615	0.0693	0.39355
5e+12	141.83	143.48	145.99	1.9563	139.49	142.13	144.33	2.0753	-2.348	-1.3508	-0.3902	0.84489
1e+13	140.21	141.96	144.43	1.7908	139.18	140.69	143.34	1.8547	-1.5574	-1.2619	-1.0369	0.24614

Device Test: 26.2 TIMING|MIN/OUT/5/5/0/0/5/500kHz//@TON_MIN

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 165.0 (ns))

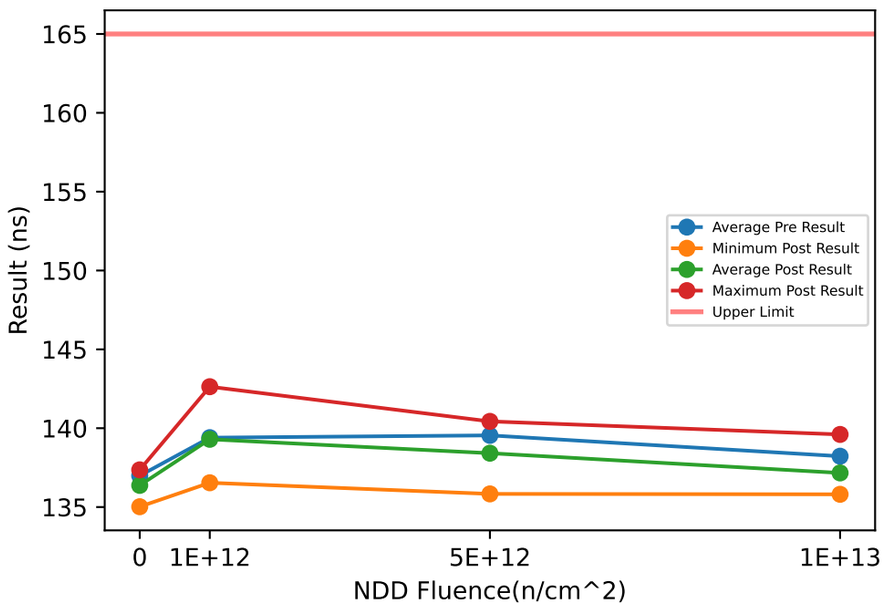
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	135.21	133.88	-1.3207
466	1e+12	NDD	137.01	136.95	-0.0673
762	0	CORRELATION	136.6	135.92	-0.6767
769	1e+12	NDD	138.85	138.92	0.0715
887	1e+12	NDD	141.78	141.49	-0.2903
891	0	CORRELATION	137.09	136.49	-0.5945
927	1e+12	NDD	136.39	135.56	-0.8306
967	5e+12	NDD	137.32	136.93	-0.3887
1204	1e+13	NDD	139.52	138.43	-1.0815
1284	1e+13	NDD	136.46	134.94	-1.5174
1292	5e+12	NDD	141.24	139.58	-1.6563
1364	1e+13	NDD	137.08	135.82	-1.2627
1383	5e+12	NDD	139.27	138.28	-0.9865
1388	5e+12	NDD	137.06	134.91	-2.1493
1427	1e+13	NDD	135.48	134.46	-1.016
1666	0	CORRELATION	135.46	135.37	-0.0837

Test Statistics (ns)

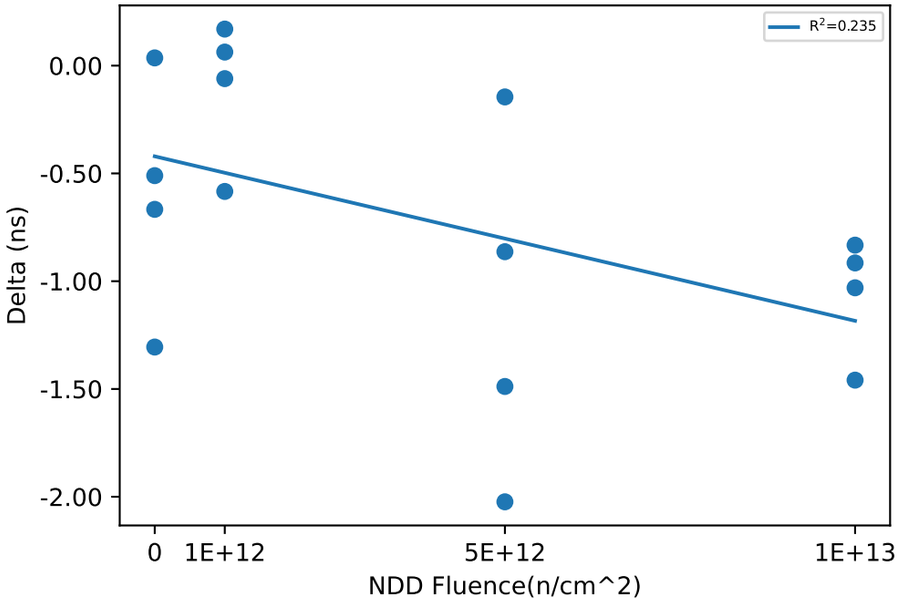
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	135.21	136.09	137.09	0.90223	133.88	135.42	136.49	1.1205	-1.3207	-0.6689	-0.0837	0.50758
1e+12	136.39	138.51	141.78	2.4172	135.56	138.23	141.49	2.5736	-0.8306	-0.27918	0.0715	0.39668
5e+12	137.06	138.72	141.24	1.947	134.91	137.43	139.58	1.9978	-2.1493	-1.2952	-0.3887	0.76961
1e+13	135.48	137.13	139.52	1.7199	134.46	135.92	138.43	1.7715	-1.5174	-1.2194	-1.016	0.2244

Device Test: 26.3 TIMING|MIN/OUT/12/12/0/0/5/500kHz//@TON_MIN

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



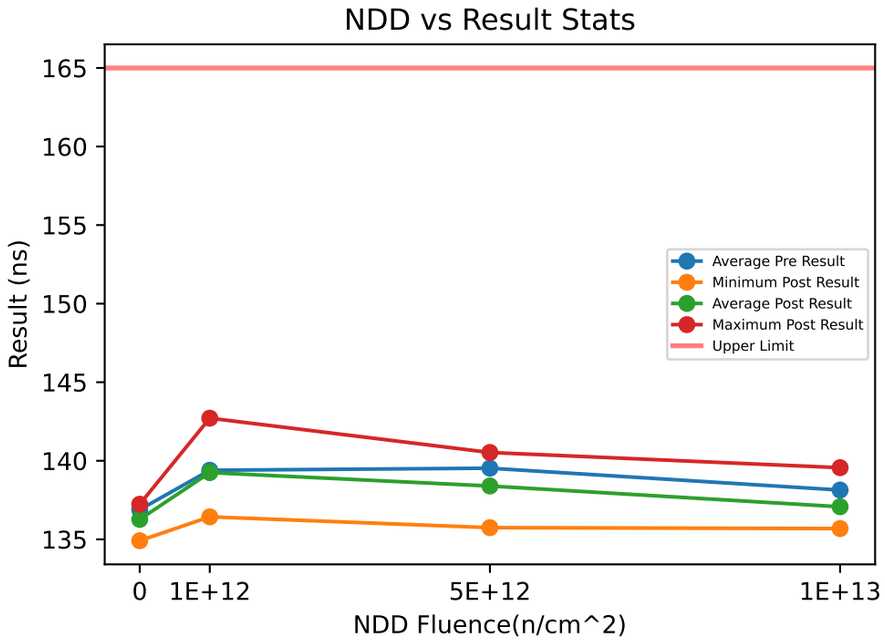
Test Results (Upper Limit = 165.0 (ns))

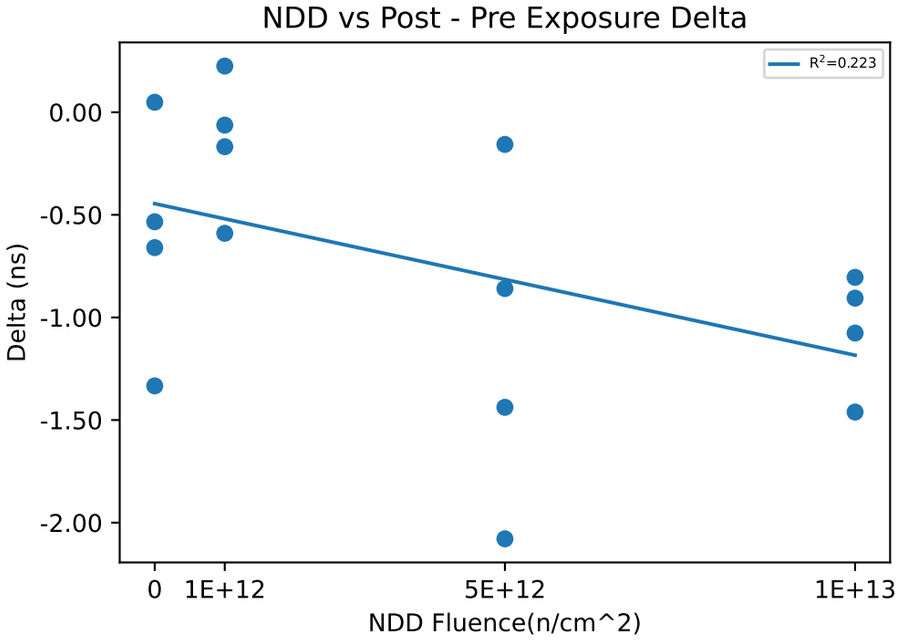
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	136.33	135.02	-1.3055
466	1e+12	NDD	137.97	138.03	0.0629
762	0	CORRELATION	137.61	136.94	-0.6667
769	1e+12	NDD	139.82	139.99	0.1696
887	1e+12	NDD	142.69	142.63	-0.0603
891	0	CORRELATION	137.87	137.36	-0.5103
927	1e+12	NDD	137.12	136.54	-0.5836
967	5e+12	NDD	138.04	137.9	-0.1452
1204	1e+13	NDD	140.44	139.6	-0.8328
1284	1e+13	NDD	137.53	136.07	-1.459
1292	5e+12	NDD	141.92	140.43	-1.4884
1364	1e+13	NDD	138.09	137.17	-0.9153
1383	5e+12	NDD	140.36	139.5	-0.8632
1388	5e+12	NDD	137.86	135.83	-2.0235
1427	1e+13	NDD	136.84	135.81	-1.0306
1666	0	CORRELATION	136.14	136.18	0.0359

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	136.14	136.99	137.87	0.87862	135.02	136.37	137.36	1.0265	-1.3055	-0.61165	0.0359	0.55198
1e+12	137.12	139.4	142.69	2.4664	136.54	139.3	142.63	2.6335	-0.5836	-0.10285	0.1696	0.33398
5e+12	137.86	139.54	141.92	1.9506	135.83	138.41	140.43	2.0141	-2.0235	-1.1301	-0.1452	0.8099
1e+13	136.84	138.22	140.44	1.5618	135.81	137.16	139.6	1.7308	-1.459	-1.0594	-0.8328	0.27846

Device Test: 26.4 TIMING|MIN/OUT/14/14/0/0/5/500kHz//@TON_MIN





Test Results (Upper Limit = 165.0 (ns))

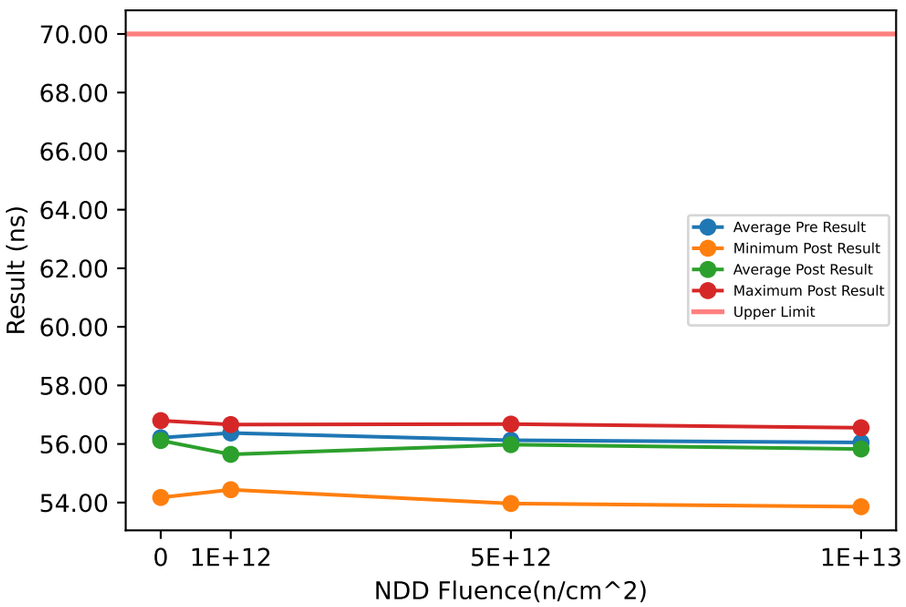
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	136.24	134.91	-1.3335
466	1e+12	NDD	137.95	137.88	-0.0628
762	0	CORRELATION	137.53	136.87	-0.6598
769	1e+12	NDD	139.73	139.96	0.2249
887	1e+12	NDD	142.88	142.71	-0.168
891	0	CORRELATION	137.77	137.23	-0.5338
927	1e+12	NDD	137.02	136.43	-0.59
967	5e+12	NDD	137.94	137.78	-0.1569
1204	1e+13	NDD	140.36	139.56	-0.8047
1284	1e+13	NDD	137.44	135.98	-1.4612
1292	5e+12	NDD	141.97	140.53	-1.438
1364	1e+13	NDD	137.98	137.07	-0.906
1383	5e+12	NDD	140.38	139.52	-0.8592
1388	5e+12	NDD	137.82	135.74	-2.0788
1427	1e+13	NDD	136.76	135.68	-1.0761
1666	0	CORRELATION	136.01	136.05	0.0486

Test Statistics (ns)

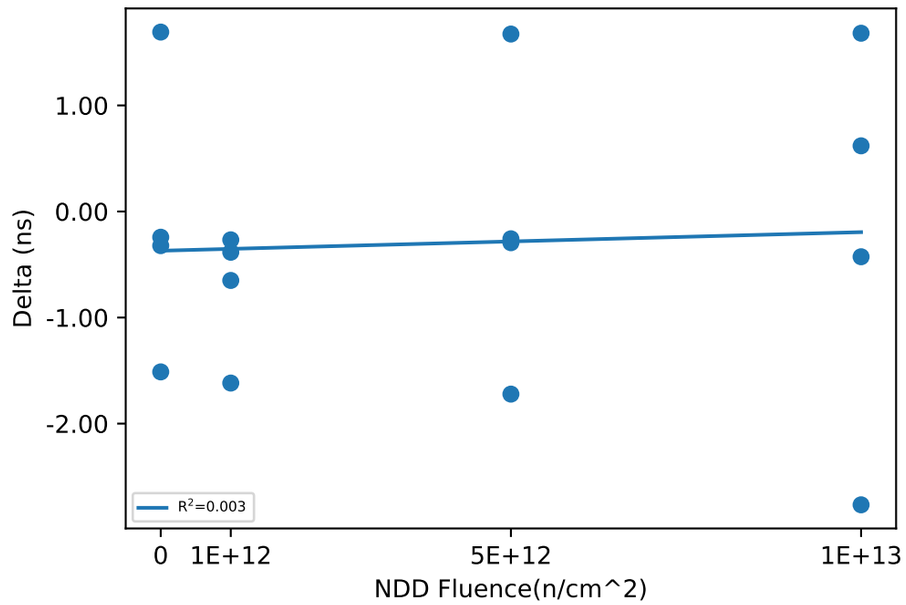
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	136.01	136.89	137.77	0.89127	134.91	136.27	137.23	1.0306	-1.3335	-0.61962	0.0486	0.56719
1e+12	137.02	139.4	142.88	2.5805	136.43	139.25	142.71	2.7254	-0.59	-0.14897	0.2249	0.33768
5e+12	137.82	139.53	141.97	2.0097	135.74	138.39	140.53	2.1001	-2.0788	-1.1332	-0.1569	0.81961
1e+13	136.76	138.14	140.36	1.5676	135.68	137.07	139.56	1.7623	-1.4612	-1.062	-0.8047	0.28873

Device Test: 26.5 TIMING|EXT/OUT/4.5/4.5/0/0/4.5/500kHz//@T_OFF_EXTENDER

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 70.0 (ns))

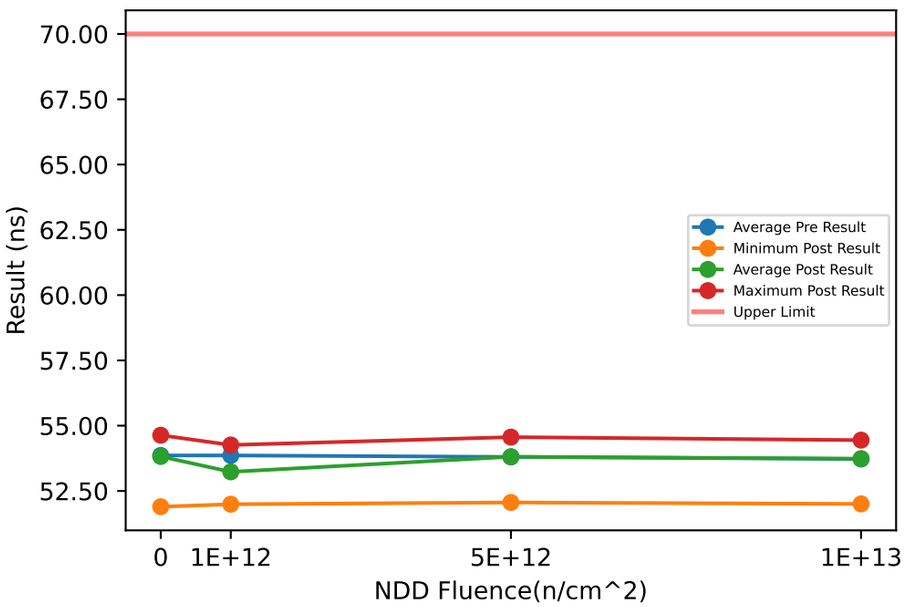
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	55.03	56.721	1.6915
466	1e+12	NDD	55.697	55.047	-0.6502
762	0	CORRELATION	57.099	56.777	-0.3221
769	1e+12	NDD	56.055	54.438	-1.6176
887	1e+12	NDD	57.047	56.663	-0.3844
891	0	CORRELATION	57.04	56.798	-0.2426
927	1e+12	NDD	56.7	56.432	-0.2672
967	5e+12	NDD	55.689	53.967	-1.7218
1204	1e+13	NDD	56.974	56.547	-0.4268
1284	1e+13	NDD	54.675	56.356	1.6806
1292	5e+12	NDD	56.9	56.605	-0.2945
1364	1e+13	NDD	55.935	56.554	0.6191
1383	5e+12	NDD	56.915	56.658	-0.2575
1388	5e+12	NDD	55.006	56.679	1.6729
1427	1e+13	NDD	56.623	53.858	-2.7656
1666	0	CORRELATION	55.685	54.173	-1.5124

Test Statistics (ns)

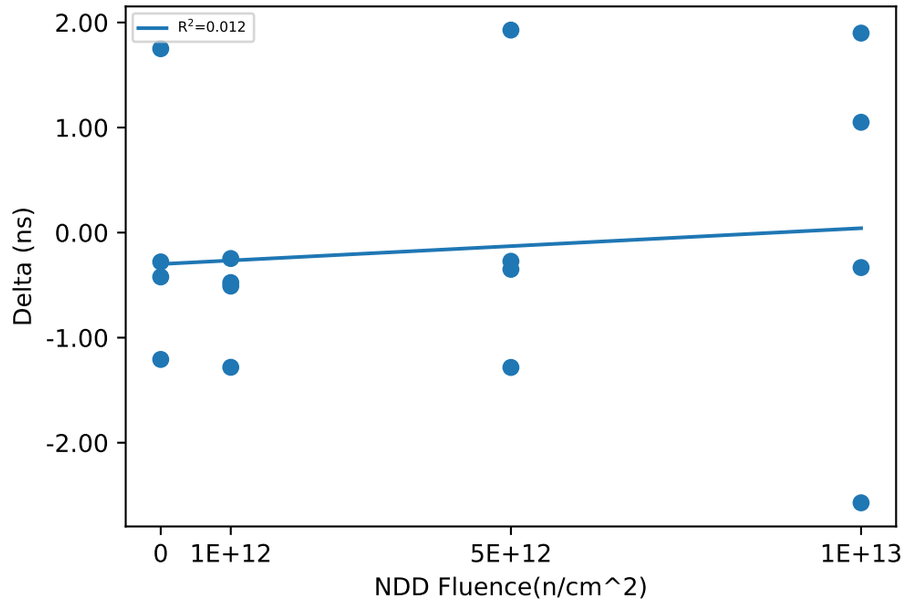
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	55.03	56.214	57.099	1.0245	54.173	56.117	56.798	1.2965	-1.5124	-0.0964	1.6915	1.3259
1e+12	55.697	56.375	57.047	0.61066	54.438	55.645	56.663	1.0757	-1.6176	-0.72985	-0.2672	0.61314
5e+12	55.006	56.127	56.915	0.94286	53.967	55.977	56.679	1.3404	-1.7218	-0.15023	1.6729	1.3936
1e+13	54.675	56.052	56.974	1.0142	53.858	55.829	56.554	1.3172	-2.7656	-0.22317	1.6806	1.9008

Device Test: 26.7 TIMING|EXT/OUT/14/14/0/0/5/500kHz//@T_OFF_EXTENDER

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 70.0 (ns))

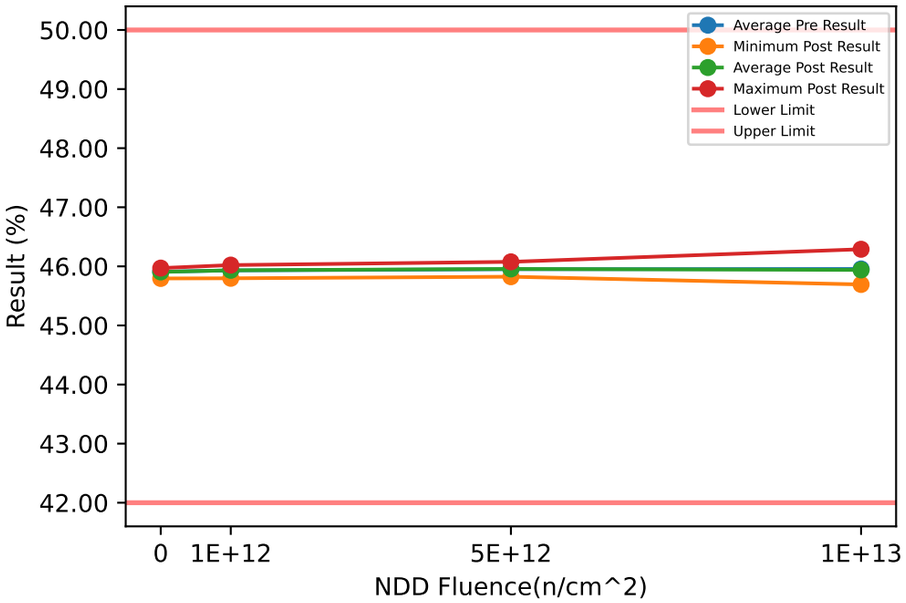
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	52.884	54.634	1.7503
466	1e+12	NDD	52.951	52.442	-0.5093
762	0	CORRELATION	54.534	54.255	-0.279
769	1e+12	NDD	53.274	51.992	-1.2821
887	1e+12	NDD	54.48	54.233	-0.2468
891	0	CORRELATION	54.918	54.496	-0.4219
927	1e+12	NDD	54.736	54.261	-0.4758
967	5e+12	NDD	53.343	52.06	-1.2835
1204	1e+13	NDD	54.522	54.19	-0.3329
1284	1e+13	NDD	52.406	54.304	1.8987
1292	5e+12	NDD	54.684	54.335	-0.3496
1364	1e+13	NDD	53.396	54.446	1.0501
1383	5e+12	NDD	54.553	54.281	-0.2728
1388	5e+12	NDD	52.634	54.561	1.9277
1427	1e+13	NDD	54.576	52.004	-2.5721
1666	0	CORRELATION	53.104	51.897	-1.2073

Test Statistics (ns)

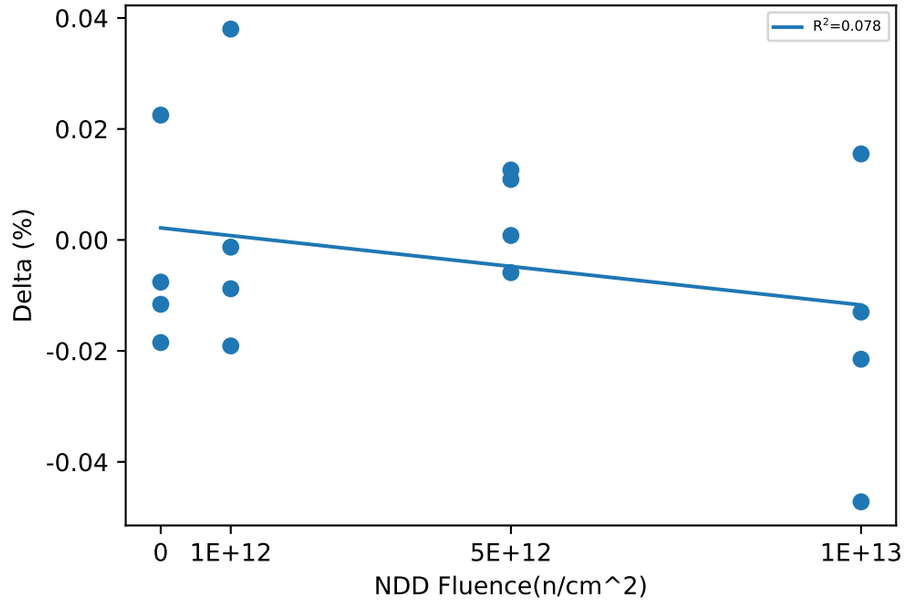
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	52.884	53.86	54.918	1.0161	51.897	53.82	54.634	1.2921	-1.2073	-0.039475	1.7503	1.261
1e+12	52.951	53.86	54.736	0.87963	51.992	53.232	54.261	1.1863	-1.2821	-0.6285	-0.2468	0.45108
5e+12	52.634	53.804	54.684	0.98638	52.06	53.809	54.561	1.1726	-1.2835	0.00545	1.9277	1.3614
1e+13	52.406	53.725	54.576	1.0343	52.004	53.736	54.446	1.1594	-2.5721	0.01095	1.8987	1.9522

Device Test: 27.17 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

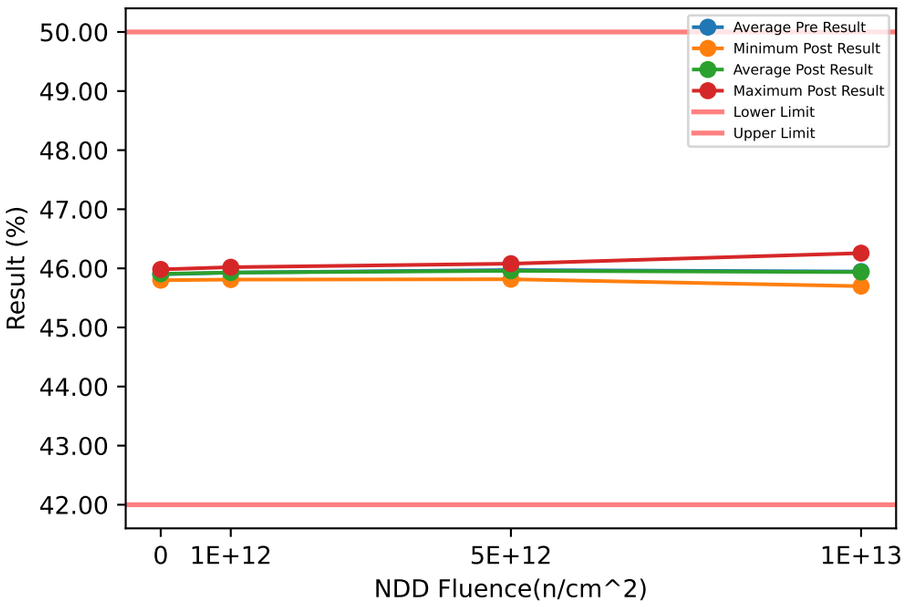
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.926	45.949	0.0225
466	1e+12	NDD	45.799	45.798	-0.0013
762	0	CORRELATION	45.978	45.97	-0.0076
769	1e+12	NDD	45.909	45.9	-0.0088
887	1e+12	NDD	46.033	46.014	-0.0191
891	0	CORRELATION	45.814	45.795	-0.0185
927	1e+12	NDD	45.983	46.021	0.038
967	5e+12	NDD	45.919	45.932	0.0126
1204	1e+13	NDD	45.78	45.758	-0.0215
1284	1e+13	NDD	45.741	45.694	-0.0472
1292	5e+12	NDD	45.813	45.824	0.0109
1364	1e+13	NDD	46.274	46.289	0.0155
1383	5e+12	NDD	45.991	45.992	0.0008
1388	5e+12	NDD	46.082	46.076	-0.0059
1427	1e+13	NDD	46.029	46.016	-0.013
1666	0	CORRELATION	45.919	45.907	-0.0116

Test Statistics (%)

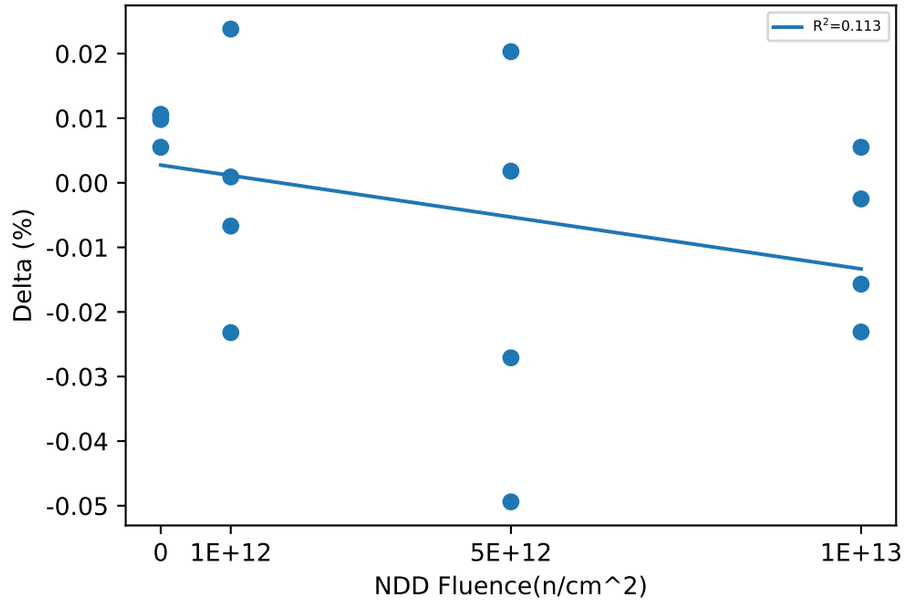
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.814	45.909	45.978	0.068878	45.795	45.905	45.97	0.078006	-0.0185	-0.0038	0.0225	0.018102
1e+12	45.799	45.931	46.033	0.10162	45.798	45.933	46.021	0.1059	-0.0191	0.0022	0.038	0.024957
5e+12	45.813	45.951	46.082	0.11356	45.824	45.956	46.076	0.10586	-0.0059	0.0046	0.0126	0.0087251
1e+13	45.741	45.956	46.274	0.24742	45.694	45.939	46.289	0.2717	-0.0472	-0.01655	0.0155	0.025844

Device Test: 27.18 LEVEL|DCL/OUT/5/5/0/0/5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

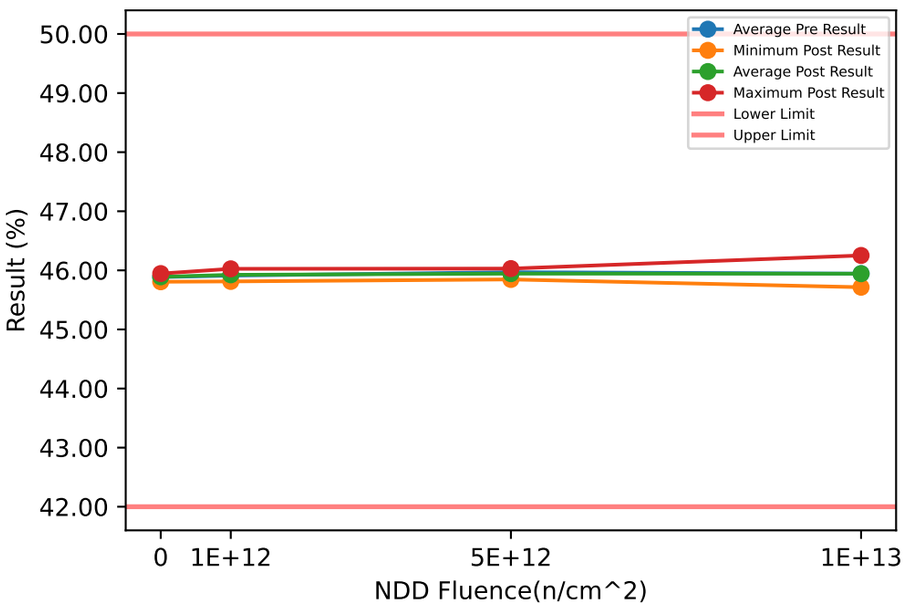
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.925	45.934	0.0098
466	1e+12	NDD	45.809	45.81	0.0009
762	0	CORRELATION	45.971	45.982	0.0106
769	1e+12	NDD	45.876	45.9	0.0238
887	1e+12	NDD	46.042	46.019	-0.0232
891	0	CORRELATION	45.789	45.799	0.0104
927	1e+12	NDD	45.989	45.982	-0.0067
967	5e+12	NDD	45.923	45.943	0.0203
1204	1e+13	NDD	45.756	45.761	0.0055
1284	1e+13	NDD	45.721	45.698	-0.0231
1292	5e+12	NDD	45.865	45.815	-0.0494
1364	1e+13	NDD	46.26	46.257	-0.0025
1383	5e+12	NDD	45.992	45.994	0.0018
1388	5e+12	NDD	46.106	46.079	-0.0271
1427	1e+13	NDD	46.047	46.031	-0.0157
1666	0	CORRELATION	45.909	45.914	0.0055

Test Statistics (%)

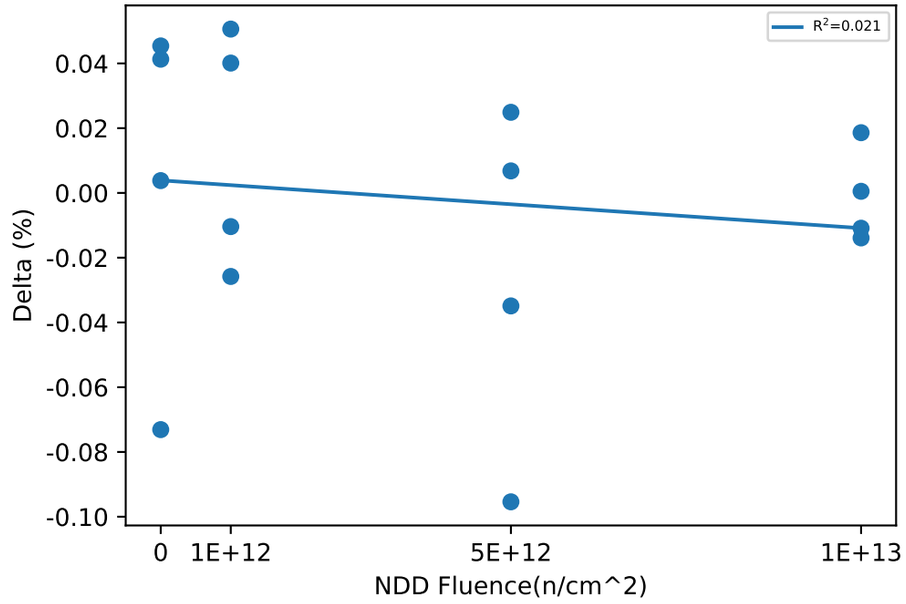
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.789	45.898	45.971	0.077644	45.799	45.907	45.982	0.07746	0.0055	0.009075	0.0106	0.0024075
1e+12	45.809	45.929	46.042	0.10598	45.81	45.928	46.019	0.093197	-0.0232	-0.0013	0.0238	0.019525
5e+12	45.865	45.971	46.106	0.10373	45.815	45.958	46.079	0.11026	-0.0494	-0.0136	0.0203	0.030823
1e+13	45.721	45.946	46.26	0.25506	45.698	45.937	46.257	0.25769	-0.0231	-0.00895	0.0055	0.012861

Device Test: 27.19 LEVEL|DCL/OUT/12/12/0/0/5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

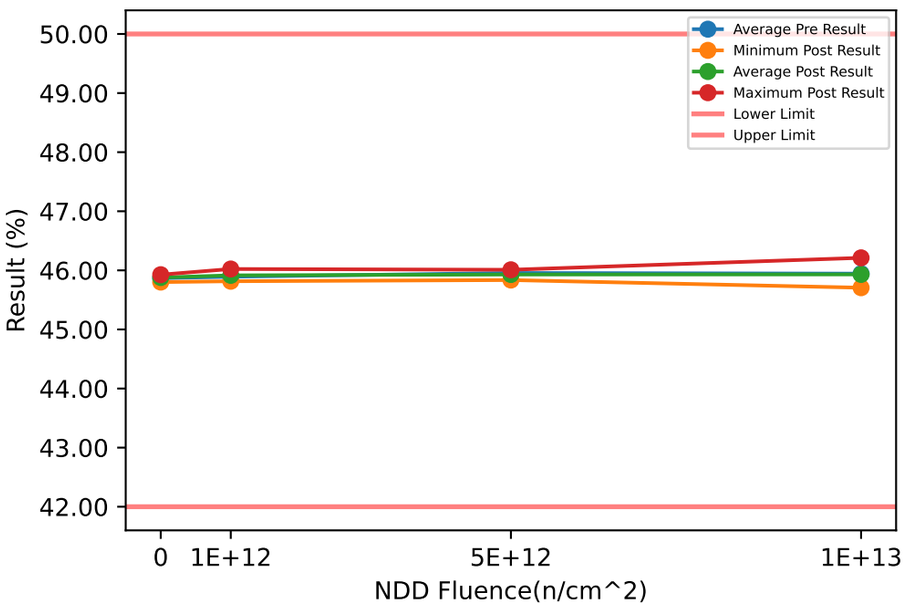
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.948	45.875	-0.0731
466	1e+12	NDD	45.823	45.813	-0.0104
762	0	CORRELATION	45.941	45.945	0.0038
769	1e+12	NDD	45.872	45.912	0.0401
887	1e+12	NDD	45.975	46.026	0.0506
891	0	CORRELATION	45.766	45.807	0.0413
927	1e+12	NDD	45.974	45.949	-0.0258
967	5e+12	NDD	45.94	45.947	0.0068
1204	1e+13	NDD	45.753	45.771	0.0186
1284	1e+13	NDD	45.728	45.714	-0.0139
1292	5e+12	NDD	45.821	45.846	0.0249
1364	1e+13	NDD	46.263	46.252	-0.0109
1383	5e+12	NDD	45.988	45.953	-0.0349
1388	5e+12	NDD	46.125	46.03	-0.0954
1427	1e+13	NDD	46.034	46.035	0.0005
1666	0	CORRELATION	45.888	45.934	0.0454

Test Statistics (%)

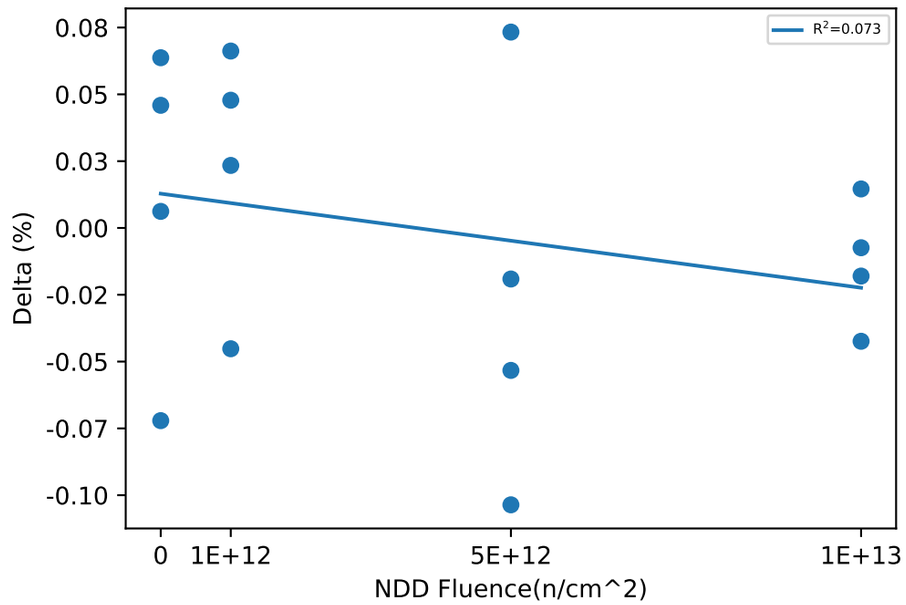
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.766	45.886	45.948	0.08451	45.807	45.89	45.945	0.063512	-0.0731	0.00435	0.0454	0.054922
1e+12	45.823	45.911	45.975	0.076177	45.813	45.925	46.026	0.088511	-0.0258	0.013625	0.0506	0.037415
5e+12	45.821	45.969	46.125	0.12562	45.846	45.944	46.03	0.075257	-0.0954	-0.02465	0.0249	0.053401
1e+13	45.728	45.944	46.263	0.25354	45.714	45.943	46.252	0.24868	-0.0139	-0.001425	0.0186	0.014721

Device Test: 27.20 LEVEL|DCL/OUT/14/14/0/0/5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

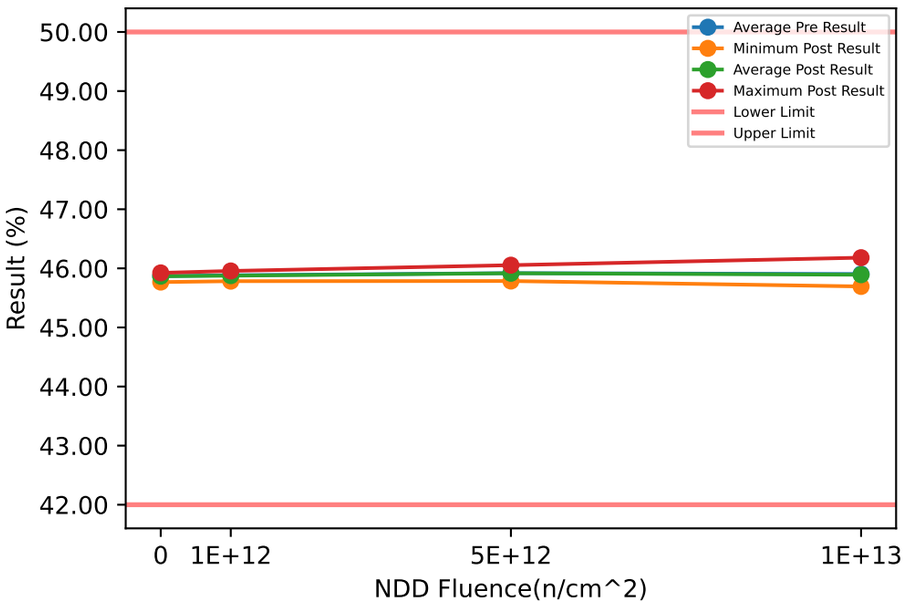
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.932	45.86	-0.0721
466	1e+12	NDD	45.792	45.816	0.0234
762	0	CORRELATION	45.92	45.926	0.0062
769	1e+12	NDD	45.857	45.905	0.0478
887	1e+12	NDD	45.956	46.023	0.0662
891	0	CORRELATION	45.755	45.801	0.0459
927	1e+12	NDD	45.963	45.918	-0.0452
967	5e+12	NDD	45.871	45.944	0.0733
1204	1e+13	NDD	45.766	45.758	-0.0074
1284	1e+13	NDD	45.748	45.706	-0.0424
1292	5e+12	NDD	45.855	45.836	-0.0191
1364	1e+13	NDD	46.23	46.212	-0.018
1383	5e+12	NDD	45.983	45.93	-0.0533
1388	5e+12	NDD	46.113	46.01	-0.1036
1427	1e+13	NDD	46.034	46.049	0.0146
1666	0	CORRELATION	45.861	45.925	0.0637

Test Statistics (%)

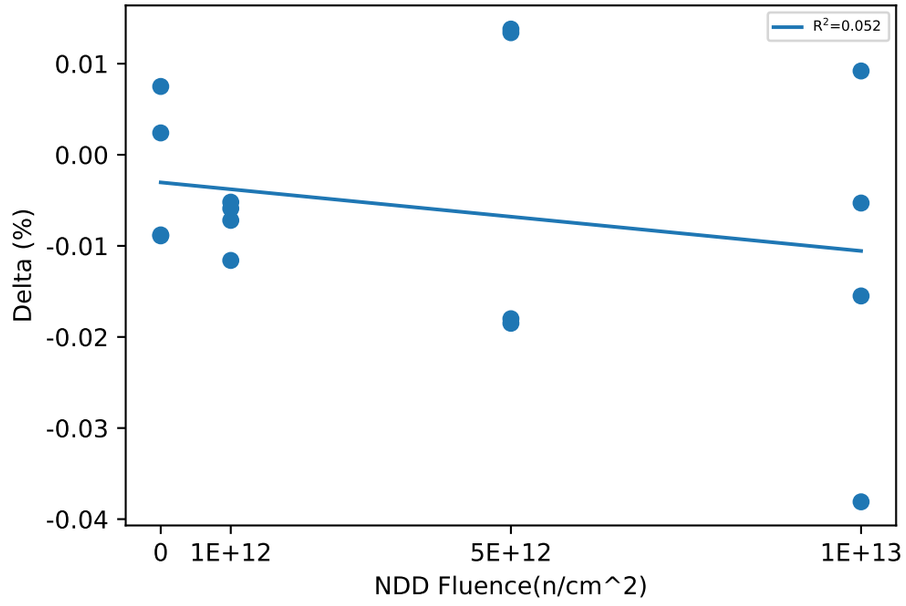
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.755	45.867	45.932	0.080802	45.801	45.878	45.926	0.059749	-0.0721	0.010925	0.0637	0.060343
1e+12	45.792	45.892	45.963	0.082439	45.816	45.915	46.023	0.084761	-0.0452	0.02305	0.0662	0.04876
5e+12	45.855	45.955	46.113	0.11951	45.836	45.93	46.01	0.071644	-0.1036	-0.025675	0.0733	0.074554
1e+13	45.748	45.944	46.23	0.23079	45.706	45.931	46.212	0.2402	-0.0424	-0.0133	0.0146	0.023679

Device Test: 27.21 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

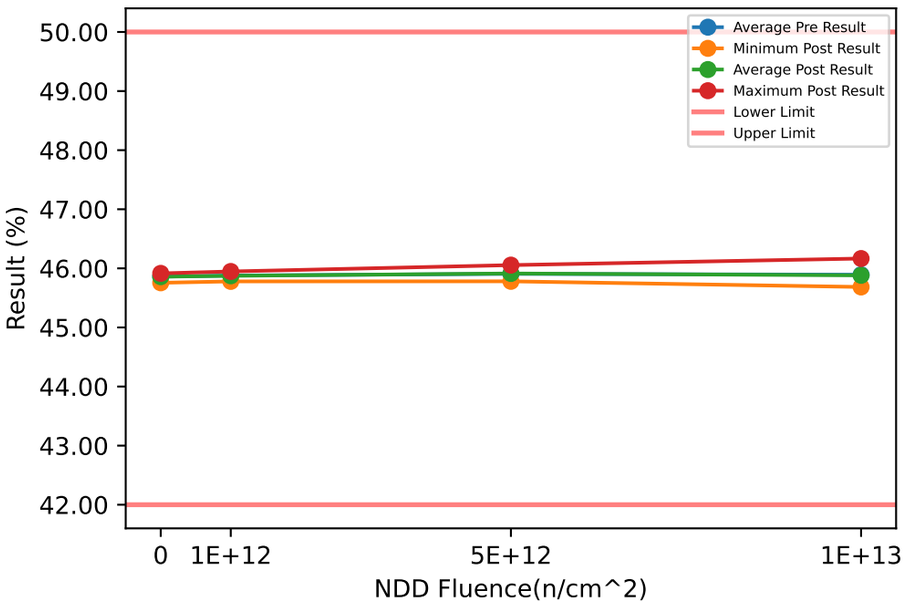
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.932	45.923	-0.0088
466	1e+12	NDD	45.79	45.783	-0.0072
762	0	CORRELATION	45.898	45.906	0.0075
769	1e+12	NDD	45.847	45.841	-0.0059
887	1e+12	NDD	45.968	45.956	-0.0116
891	0	CORRELATION	45.765	45.767	0.0024
927	1e+12	NDD	45.928	45.923	-0.0052
967	5e+12	NDD	45.878	45.892	0.0138
1204	1e+13	NDD	45.712	45.721	0.0092
1284	1e+13	NDD	45.732	45.694	-0.0381
1292	5e+12	NDD	45.803	45.785	-0.018
1364	1e+13	NDD	46.196	46.181	-0.0155
1383	5e+12	NDD	45.923	45.936	0.0134
1388	5e+12	NDD	46.072	46.054	-0.0185
1427	1e+13	NDD	45.977	45.972	-0.0053
1666	0	CORRELATION	45.879	45.87	-0.0089

Test Statistics (%)

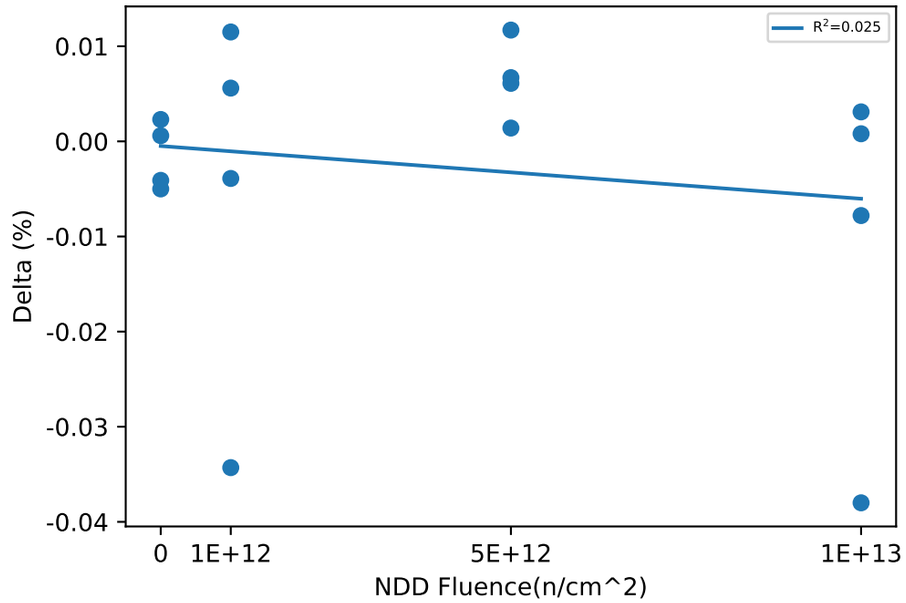
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.765	45.868	45.932	0.072383	45.767	45.867	45.923	0.069709	-0.0089	-0.00195	0.0075	0.0082351
1e+12	45.79	45.883	45.968	0.079762	45.783	45.876	45.956	0.078433	-0.0116	-0.007475	-0.0052	0.0028721
5e+12	45.803	45.919	46.072	0.11336	45.785	45.917	46.054	0.11111	-0.0185	-0.002325	0.0138	0.01839
1e+13	45.712	45.904	46.196	0.22886	45.694	45.892	46.181	0.22957	-0.0381	-0.012425	0.0092	0.019892

Device Test: 27.22 LEVEL|DCL/OUT/5/5/0/0/5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

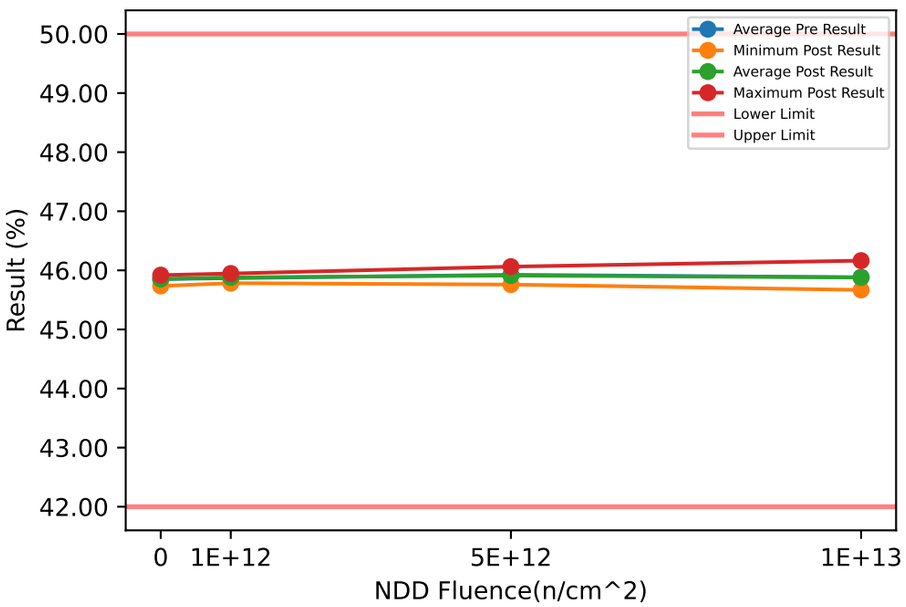
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.914	45.915	0.0006
466	1e+12	NDD	45.783	45.779	-0.0039
762	0	CORRELATION	45.911	45.907	-0.005
769	1e+12	NDD	45.837	45.848	0.0115
887	1e+12	NDD	45.981	45.947	-0.0343
891	0	CORRELATION	45.753	45.756	0.0023
927	1e+12	NDD	45.914	45.92	0.0056
967	5e+12	NDD	45.873	45.885	0.0117
1204	1e+13	NDD	45.703	45.704	0.0008
1284	1e+13	NDD	45.723	45.685	-0.038
1292	5e+12	NDD	45.779	45.781	0.0014
1364	1e+13	NDD	46.174	46.166	-0.0078
1383	5e+12	NDD	45.927	45.933	0.0061
1388	5e+12	NDD	46.048	46.055	0.0067
1427	1e+13	NDD	45.969	45.972	0.0031
1666	0	CORRELATION	45.861	45.857	-0.0041

Test Statistics (%)

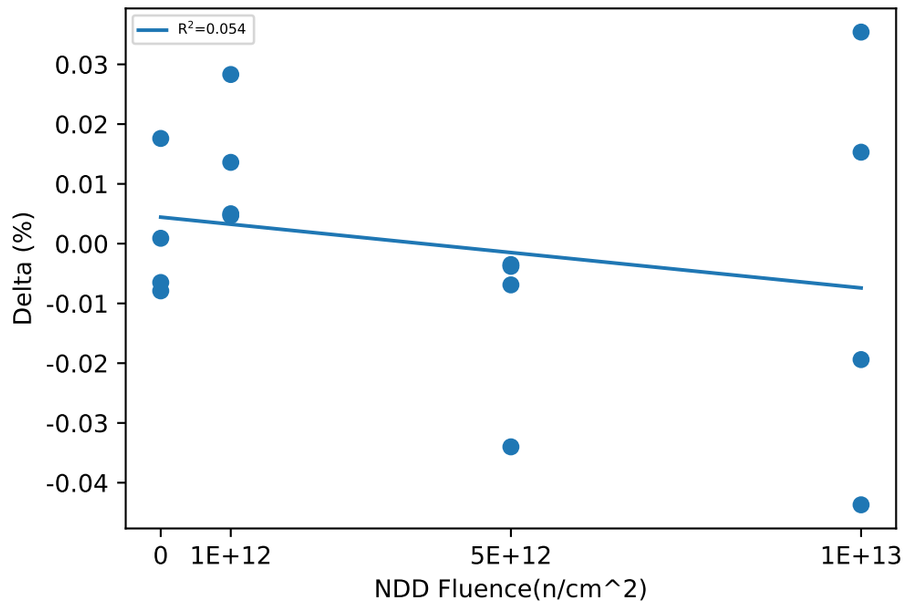
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.753	45.86	45.914	0.075249	45.756	45.859	45.915	0.073201	-0.005	-0.00155	0.0023	0.003552
1e+12	45.783	45.879	45.981	0.087003	45.779	45.874	45.947	0.075464	-0.0343	-0.005275	0.0115	0.020363
5e+12	45.779	45.907	46.048	0.11227	45.781	45.913	46.055	0.11381	0.0014	0.006475	0.0117	0.004213
1e+13	45.703	45.892	46.174	0.22321	45.685	45.882	46.166	0.23036	-0.038	-0.010475	0.0031	0.01894

Device Test: 27.23 LEVEL|DCL/OUT/12/12/0/0/5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

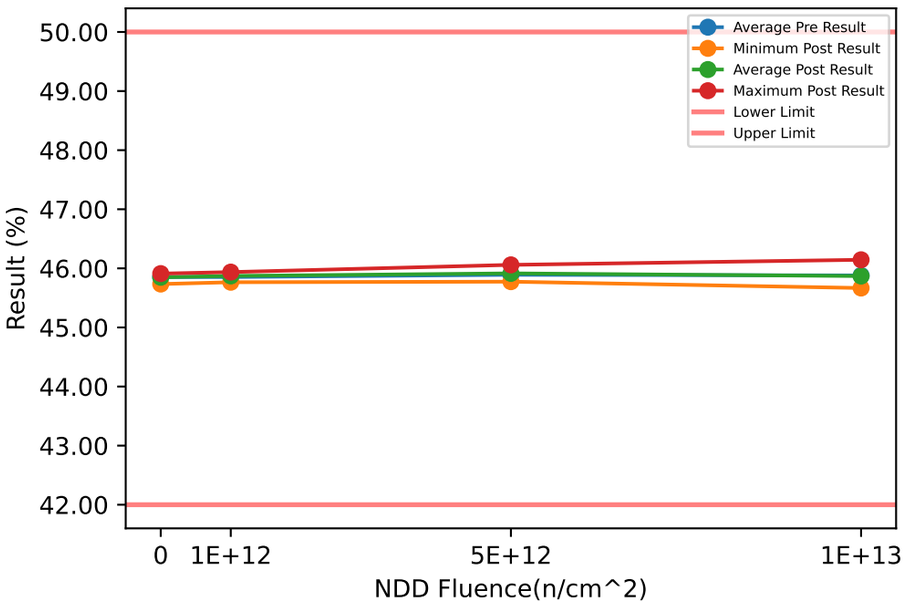
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.901	45.919	0.0176
466	1e+12	NDD	45.779	45.783	0.0047
762	0	CORRELATION	45.888	45.889	0.0009
769	1e+12	NDD	45.834	45.848	0.0136
887	1e+12	NDD	45.941	45.946	0.005
891	0	CORRELATION	45.742	45.736	-0.0065
927	1e+12	NDD	45.918	45.946	0.0283
967	5e+12	NDD	45.895	45.891	-0.0038
1204	1e+13	NDD	45.672	45.707	0.0354
1284	1e+13	NDD	45.712	45.668	-0.0437
1292	5e+12	NDD	45.793	45.759	-0.034
1364	1e+13	NDD	46.184	46.164	-0.0194
1383	5e+12	NDD	45.943	45.936	-0.0069
1388	5e+12	NDD	46.066	46.063	-0.0035
1427	1e+13	NDD	45.963	45.978	0.0153
1666	0	CORRELATION	45.876	45.868	-0.0079

Test Statistics (%)

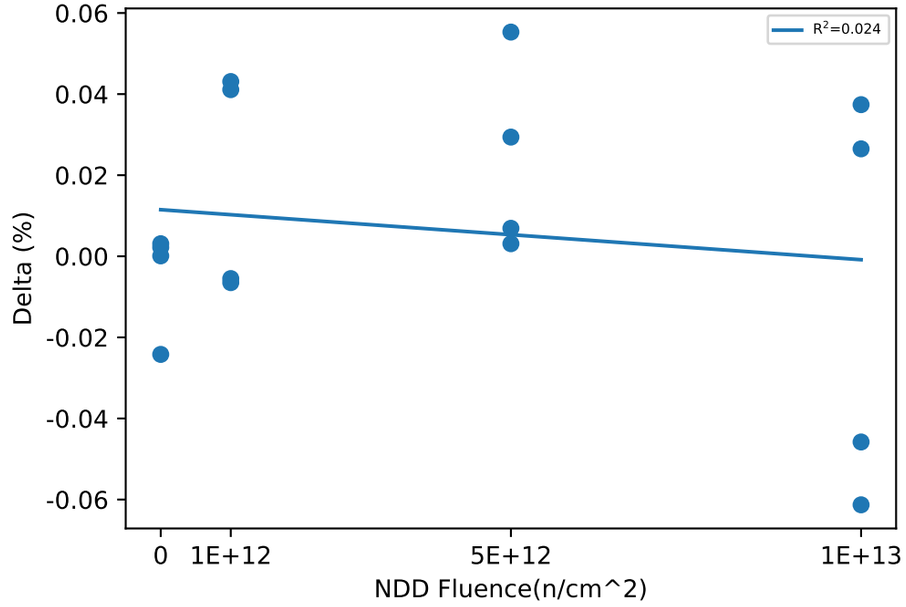
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.742	45.852	45.901	0.073784	45.736	45.853	45.919	0.080828	-0.0079	0.001025	0.0176	0.011705
1e+12	45.779	45.868	45.941	0.075233	45.783	45.881	45.946	0.079881	0.0047	0.0129	0.0283	0.011065
5e+12	45.793	45.924	46.066	0.11341	45.759	45.912	46.063	0.12533	-0.034	-0.01205	-0.0035	0.014714
1e+13	45.672	45.883	46.184	0.23843	45.668	45.879	46.164	0.23454	-0.0437	-0.0031	0.0354	0.035284

Device Test: 27.24 LEVEL|DCL/OUT/14/14/0/0/5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

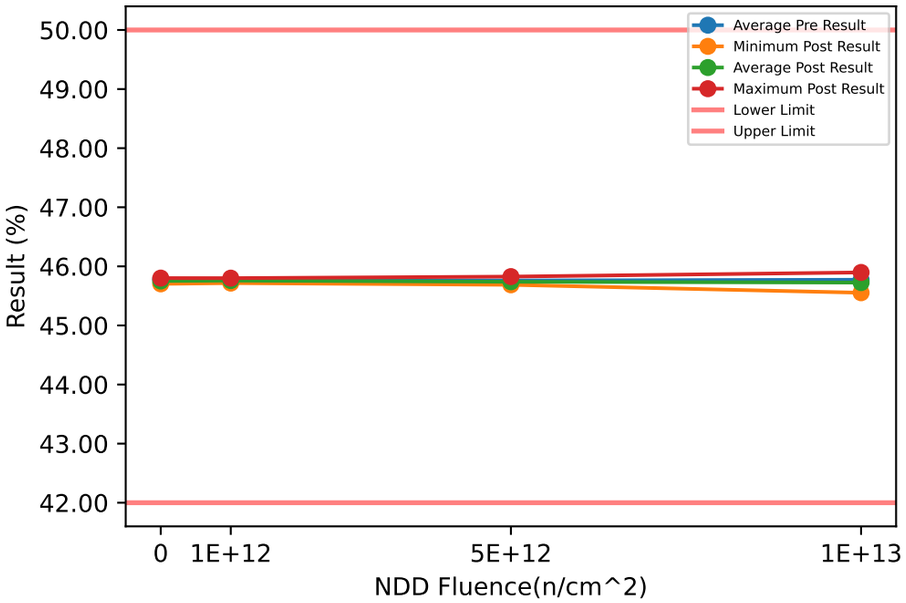
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.909	45.911	0.0022
466	1e+12	NDD	45.771	45.765	-0.0055
762	0	CORRELATION	45.894	45.897	0.0031
769	1e+12	NDD	45.816	45.857	0.0411
887	1e+12	NDD	45.943	45.937	-0.0065
891	0	CORRELATION	45.734	45.734	0.0001
927	1e+12	NDD	45.884	45.927	0.0431
967	5e+12	NDD	45.882	45.885	0.0031
1204	1e+13	NDD	45.664	45.691	0.0265
1284	1e+13	NDD	45.728	45.667	-0.0613
1292	5e+12	NDD	45.719	45.775	0.0553
1364	1e+13	NDD	46.191	46.145	-0.0458
1383	5e+12	NDD	45.912	45.942	0.0294
1388	5e+12	NDD	46.052	46.059	0.0069
1427	1e+13	NDD	45.937	45.975	0.0374
1666	0	CORRELATION	45.877	45.853	-0.0242

Test Statistics (%)

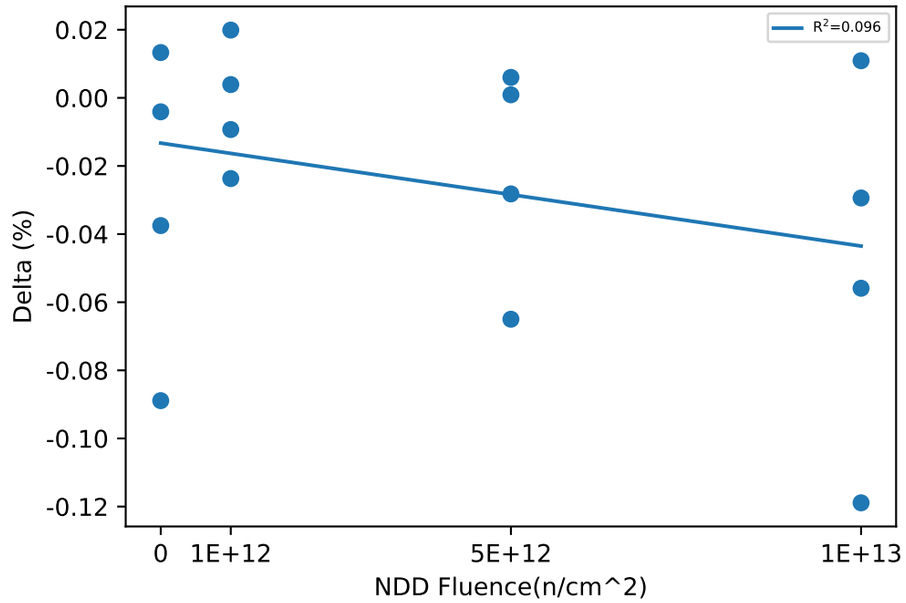
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.734	45.853	45.909	0.080528	45.734	45.849	45.911	0.080204	-0.0242	-0.0047	0.0031	0.013061
1e+12	45.771	45.853	45.943	0.075771	45.765	45.871	45.937	0.079247	-0.0065	0.01805	0.0431	0.027786
5e+12	45.719	45.891	46.052	0.13658	45.775	45.915	46.059	0.1184	0.0031	0.023675	0.0553	0.024067
1e+13	45.664	45.88	46.191	0.23745	45.667	45.869	46.145	0.2307	-0.0613	-0.0108	0.0374	0.049966

Device Test: 27.25 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

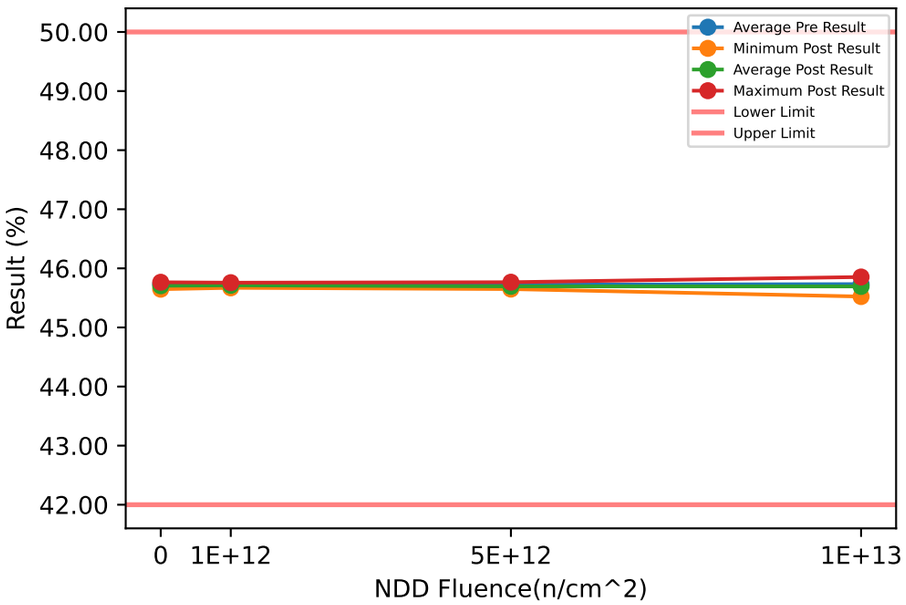
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.861	45.772	-0.0889
466	1e+12	NDD	45.736	45.74	0.0039
762	0	CORRELATION	45.769	45.732	-0.0375
769	1e+12	NDD	45.697	45.717	0.0199
887	1e+12	NDD	45.803	45.779	-0.0237
891	0	CORRELATION	45.708	45.704	-0.0041
927	1e+12	NDD	45.81	45.8	-0.0093
967	5e+12	NDD	45.751	45.752	0.0009
1204	1e+13	NDD	45.583	45.553	-0.0294
1284	1e+13	NDD	45.709	45.59	-0.1189
1292	5e+12	NDD	45.682	45.688	0.006
1364	1e+13	NDD	45.953	45.897	-0.0559
1383	5e+12	NDD	45.718	45.69	-0.0282
1388	5e+12	NDD	45.891	45.826	-0.065
1427	1e+13	NDD	45.849	45.86	0.0109
1666	0	CORRELATION	45.788	45.801	0.0133

Test Statistics (%)

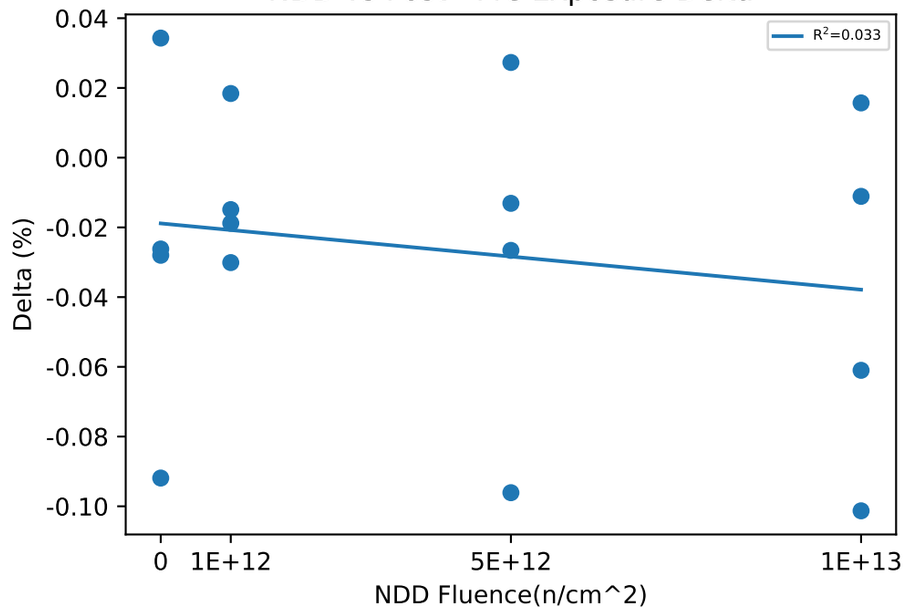
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.708	45.782	45.861	0.063137	45.704	45.752	45.801	0.043065	-0.0889	-0.0293	0.0133	0.044979
1e+12	45.697	45.761	45.81	0.05441	45.717	45.759	45.8	0.037775	-0.0237	-0.0023	0.0199	0.018603
5e+12	45.682	45.761	45.891	0.091652	45.688	45.739	45.826	0.065335	-0.065	-0.021575	0.006	0.032635
1e+13	45.583	45.773	45.953	0.16162	45.553	45.725	45.897	0.17829	-0.1189	-0.048325	0.0109	0.054479

Device Test: 27.26 LEVEL|DCL/OUT/5/5/0/0/5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

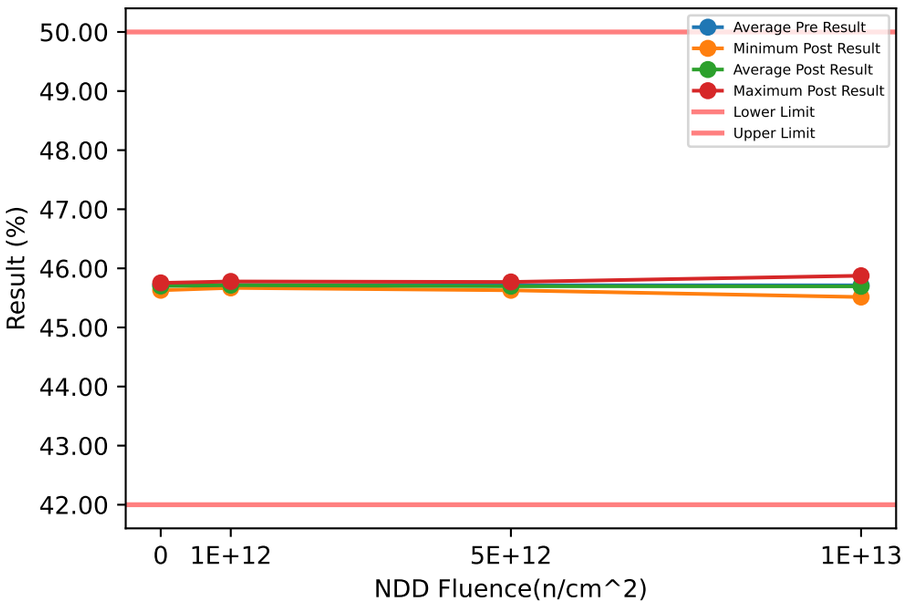
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.814	45.722	-0.0919
466	1e+12	NDD	45.709	45.69	-0.0188
762	0	CORRELATION	45.715	45.687	-0.028
769	1e+12	NDD	45.652	45.67	0.0184
887	1e+12	NDD	45.763	45.733	-0.0301
891	0	CORRELATION	45.673	45.647	-0.0262
927	1e+12	NDD	45.772	45.757	-0.0149
967	5e+12	NDD	45.69	45.717	0.0273
1204	1e+13	NDD	45.534	45.523	-0.0111
1284	1e+13	NDD	45.672	45.571	-0.1013
1292	5e+12	NDD	45.662	45.649	-0.0131
1364	1e+13	NDD	45.914	45.853	-0.061
1383	5e+12	NDD	45.676	45.649	-0.0266
1388	5e+12	NDD	45.862	45.766	-0.0961
1427	1e+13	NDD	45.812	45.828	0.0157
1666	0	CORRELATION	45.73	45.764	0.0343

Test Statistics (%)

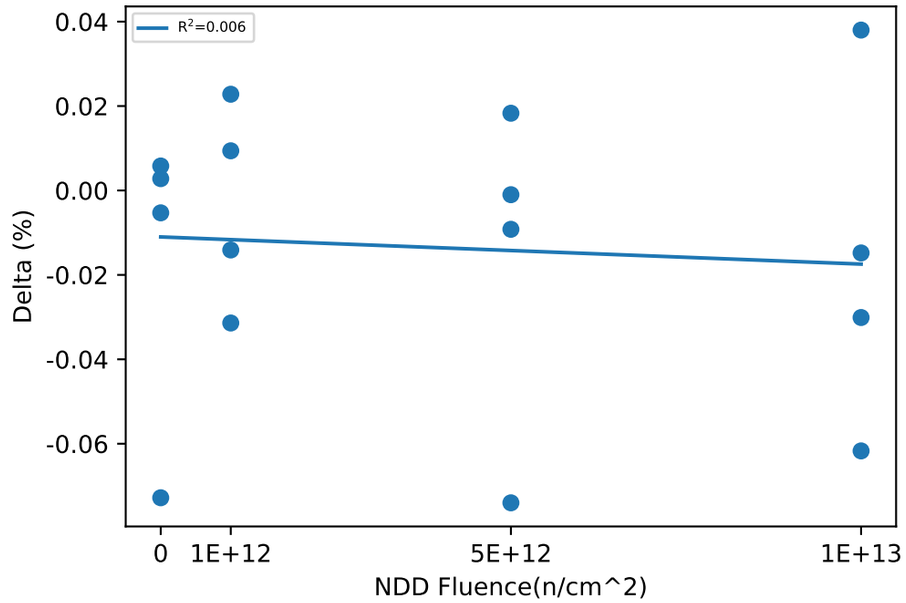
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.673	45.733	45.814	0.059098	45.647	45.705	45.764	0.049974	-0.0919	-0.02795	0.0343	0.051536
1e+12	45.652	45.724	45.772	0.055697	45.67	45.712	45.757	0.039737	-0.0301	-0.01135	0.0184	0.020854
5e+12	45.662	45.722	45.862	0.093496	45.649	45.695	45.766	0.056779	-0.0961	-0.027125	0.0273	0.05137
1e+13	45.534	45.733	45.914	0.16577	45.523	45.694	45.853	0.17101	-0.1013	-0.039425	0.0157	0.052074

Device Test: 27.27 LEVEL|DCL/OUT/12/12/0/0/5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

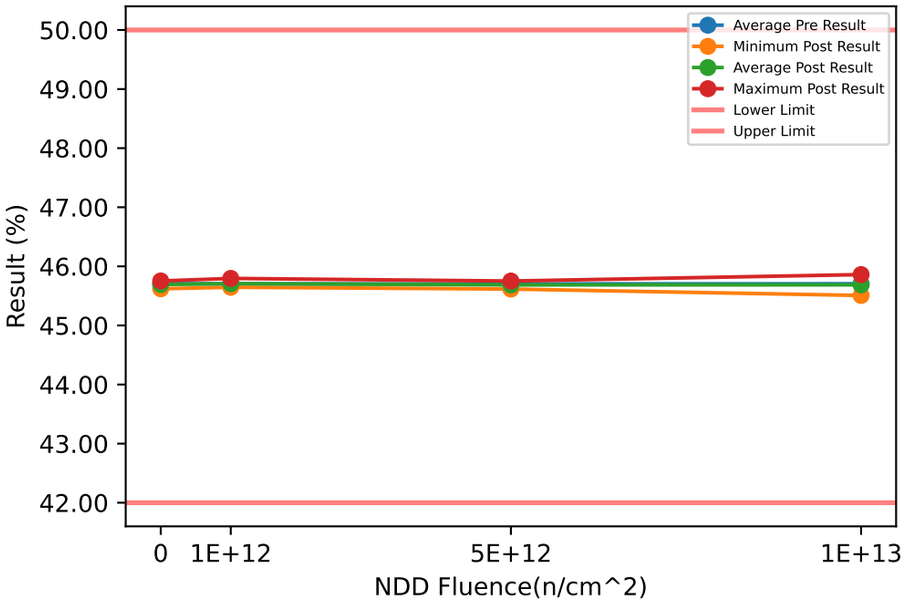
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.793	45.72	-0.0728
466	1e+12	NDD	45.694	45.68	-0.0141
762	0	CORRELATION	45.706	45.7	-0.0053
769	1e+12	NDD	45.66	45.669	0.0094
887	1e+12	NDD	45.764	45.732	-0.0314
891	0	CORRELATION	45.626	45.629	0.0028
927	1e+12	NDD	45.755	45.778	0.0228
967	5e+12	NDD	45.708	45.726	0.0183
1204	1e+13	NDD	45.529	45.514	-0.0148
1284	1e+13	NDD	45.622	45.561	-0.0617
1292	5e+12	NDD	45.638	45.629	-0.0092
1364	1e+13	NDD	45.905	45.875	-0.0301
1383	5e+12	NDD	45.666	45.665	-0.001
1388	5e+12	NDD	45.844	45.77	-0.074
1427	1e+13	NDD	45.794	45.831	0.038
1666	0	CORRELATION	45.748	45.754	0.0058

Test Statistics (%)

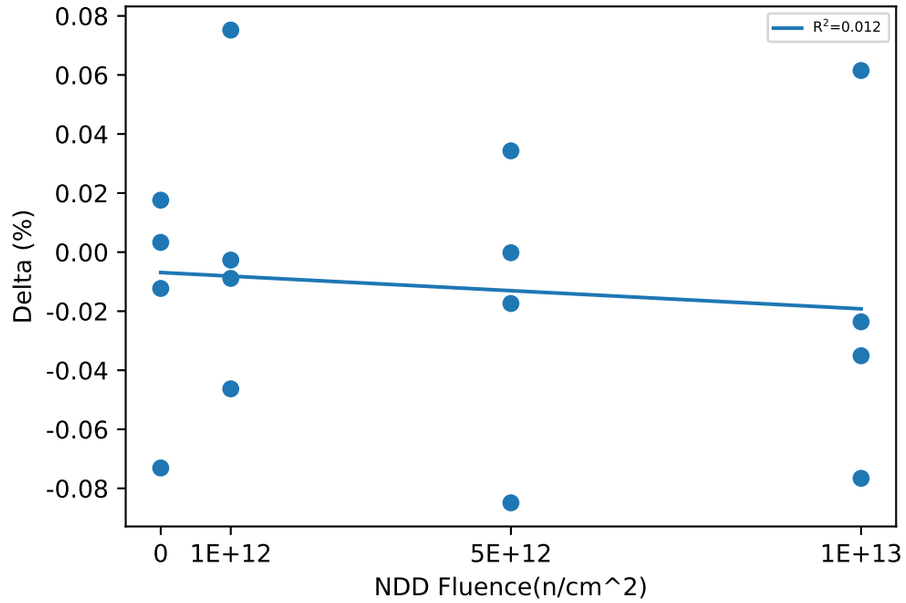
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.626	45.718	45.793	0.0709	45.629	45.701	45.754	0.052617	-0.0728	-0.017375	0.0058	0.037246
1e+12	45.66	45.718	45.764	0.049843	45.669	45.715	45.778	0.050428	-0.0314	-0.003325	0.0228	0.024144
5e+12	45.638	45.714	45.844	0.091224	45.629	45.697	45.77	0.062832	-0.074	-0.016475	0.0183	0.040045
1e+13	45.529	45.713	45.905	0.16866	45.514	45.695	45.875	0.18407	-0.0617	-0.01715	0.038	0.041631

Device Test: 27.28 LEVEL|DCL/OUT/14/14/0/0/5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

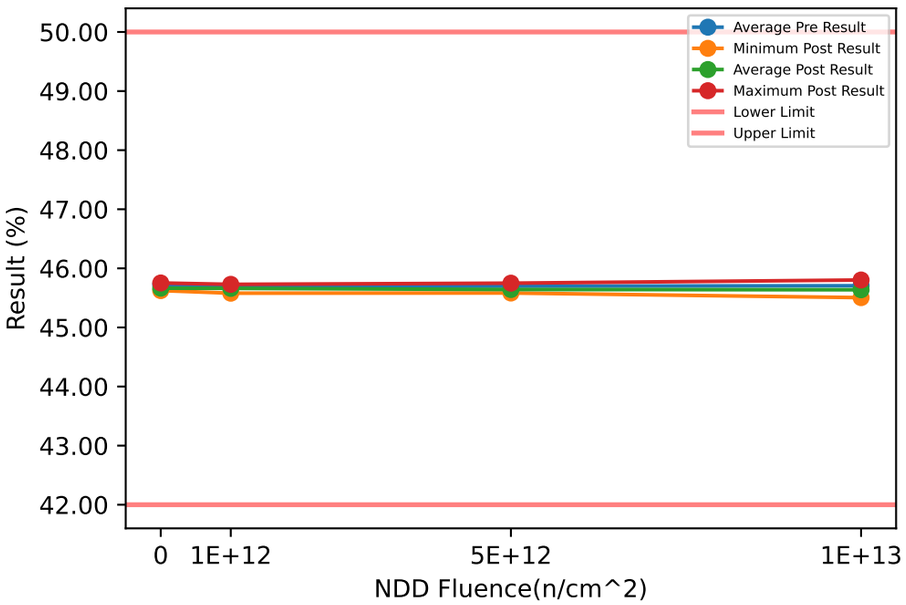
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.775	45.702	-0.0731
466	1e+12	NDD	45.676	45.673	-0.0027
762	0	CORRELATION	45.709	45.697	-0.0123
769	1e+12	NDD	45.655	45.646	-0.0089
887	1e+12	NDD	45.761	45.715	-0.0463
891	0	CORRELATION	45.617	45.621	0.0033
927	1e+12	NDD	45.72	45.796	0.0752
967	5e+12	NDD	45.686	45.72	0.0343
1204	1e+13	NDD	45.531	45.507	-0.0236
1284	1e+13	NDD	45.621	45.544	-0.0766
1292	5e+12	NDD	45.633	45.616	-0.0174
1364	1e+13	NDD	45.895	45.86	-0.0351
1383	5e+12	NDD	45.658	45.658	-0.0002
1388	5e+12	NDD	45.836	45.751	-0.0849
1427	1e+13	NDD	45.774	45.835	0.0615
1666	0	CORRELATION	45.735	45.753	0.0176

Test Statistics (%)

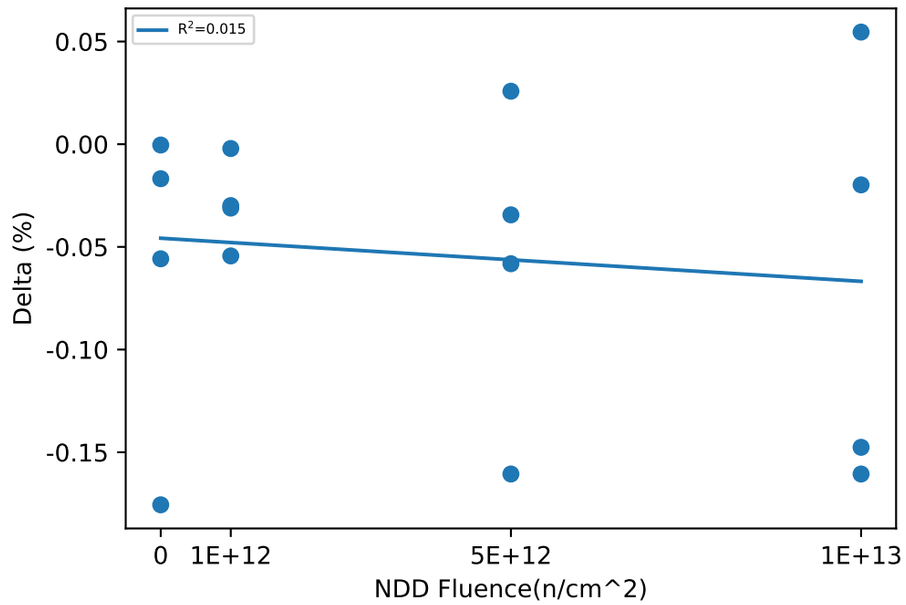
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.617	45.709	45.775	0.067027	45.621	45.693	45.753	0.054504	-0.0731	-0.016125	0.0176	0.039898
1e+12	45.655	45.703	45.761	0.047223	45.646	45.707	45.796	0.065168	-0.0463	0.004325	0.0752	0.051024
5e+12	45.633	45.703	45.836	0.091227	45.616	45.686	45.751	0.061034	-0.0849	-0.01705	0.0343	0.050082
1e+13	45.531	45.705	45.895	0.1617	45.507	45.687	45.86	0.18686	-0.0766	-0.01845	0.0615	0.057957

Device Test: 27.29 LEVEL|DCL/OUT/4.5/4.5/0/0/4.5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

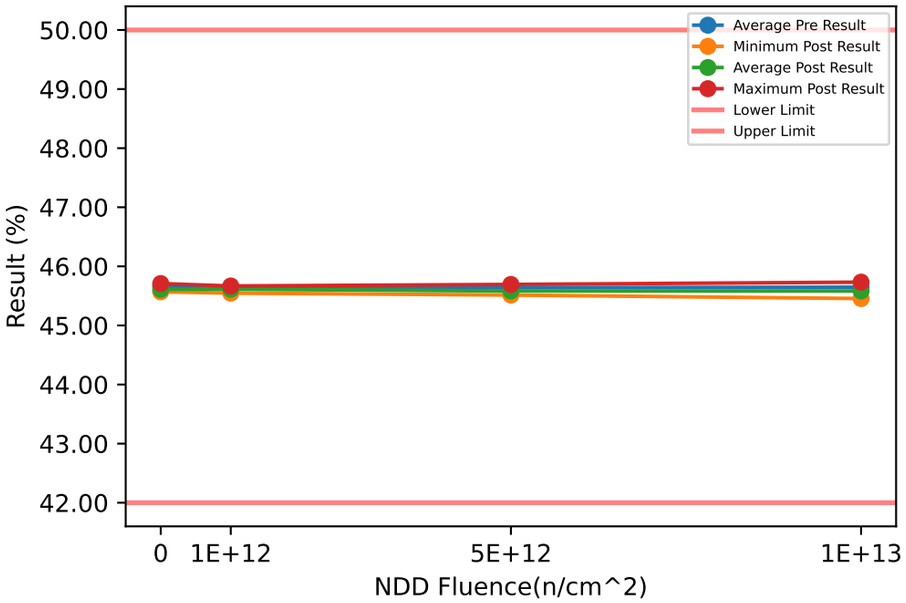
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.807	45.632	-0.1756
466	1e+12	NDD	45.705	45.674	-0.0311
762	0	CORRELATION	45.679	45.623	-0.0558
769	1e+12	NDD	45.731	45.729	-0.0021
887	1e+12	NDD	45.634	45.58	-0.0544
891	0	CORRELATION	45.665	45.649	-0.0168
927	1e+12	NDD	45.69	45.66	-0.0299
967	5e+12	NDD	45.723	45.749	0.0258
1204	1e+13	NDD	45.533	45.513	-0.0198
1284	1e+13	NDD	45.665	45.505	-0.1606
1292	5e+12	NDD	45.652	45.618	-0.0344
1364	1e+13	NDD	45.876	45.729	-0.1476
1383	5e+12	NDD	45.641	45.583	-0.0582
1388	5e+12	NDD	45.778	45.617	-0.1606
1427	1e+13	NDD	45.748	45.803	0.0546
1666	0	CORRELATION	45.753	45.752	-0.0004

Test Statistics (%)

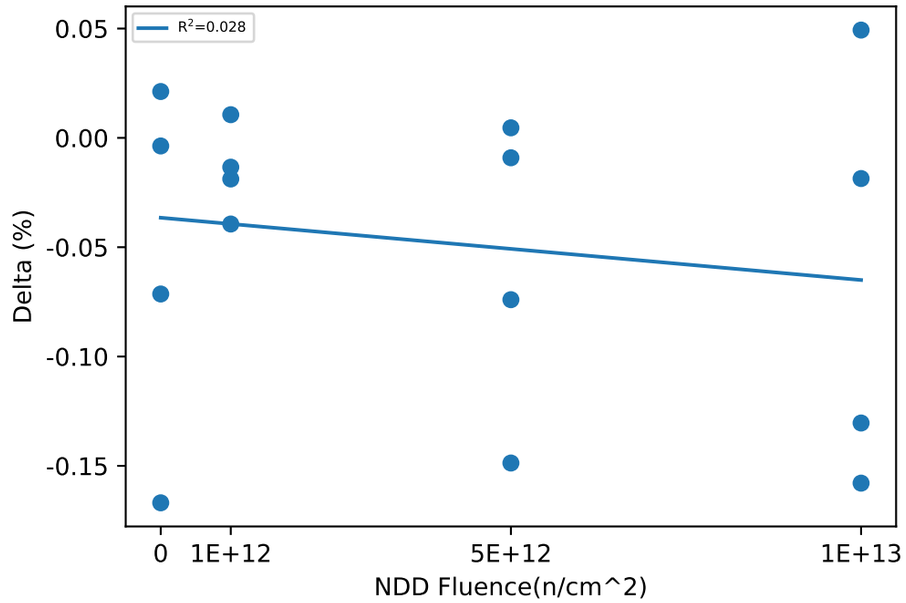
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.665	45.726	45.807	0.066203	45.623	45.664	45.752	0.059856	-0.1756	-0.06215	-0.0004	0.079122
1e+12	45.634	45.69	45.731	0.041142	45.58	45.661	45.729	0.061806	-0.0544	-0.029375	-0.0021	0.021396
5e+12	45.641	45.699	45.778	0.064102	45.583	45.642	45.749	0.07357	-0.1606	-0.05685	0.0258	0.077676
1e+13	45.533	45.706	45.876	0.14415	45.505	45.637	45.803	0.15136	-0.1606	-0.06835	0.0546	0.10371

Device Test: 27.30 LEVEL|DCL/OUT/5/5/0/0/5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

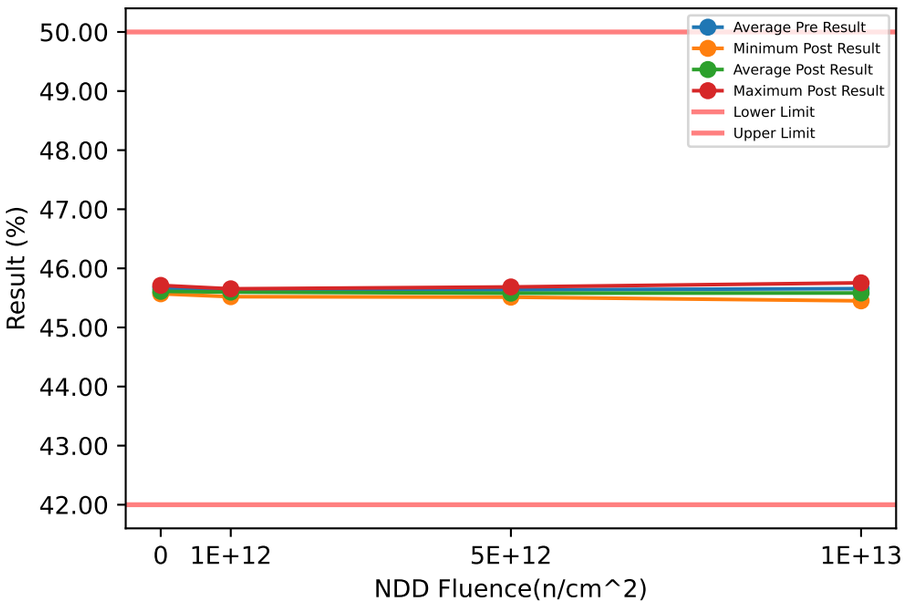
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.736	45.569	-0.1669
466	1e+12	NDD	45.642	45.629	-0.0134
762	0	CORRELATION	45.642	45.57	-0.0714
769	1e+12	NDD	45.657	45.668	0.0106
887	1e+12	NDD	45.586	45.547	-0.0394
891	0	CORRELATION	45.597	45.593	-0.0037
927	1e+12	NDD	45.625	45.606	-0.0188
967	5e+12	NDD	45.689	45.694	0.0046
1204	1e+13	NDD	45.489	45.471	-0.0186
1284	1e+13	NDD	45.613	45.455	-0.1579
1292	5e+12	NDD	45.58	45.571	-0.0091
1364	1e+13	NDD	45.803	45.673	-0.1304
1383	5e+12	NDD	45.588	45.514	-0.074
1388	5e+12	NDD	45.7	45.551	-0.1487
1427	1e+13	NDD	45.683	45.733	0.0493
1666	0	CORRELATION	45.687	45.709	0.0212

Test Statistics (%)

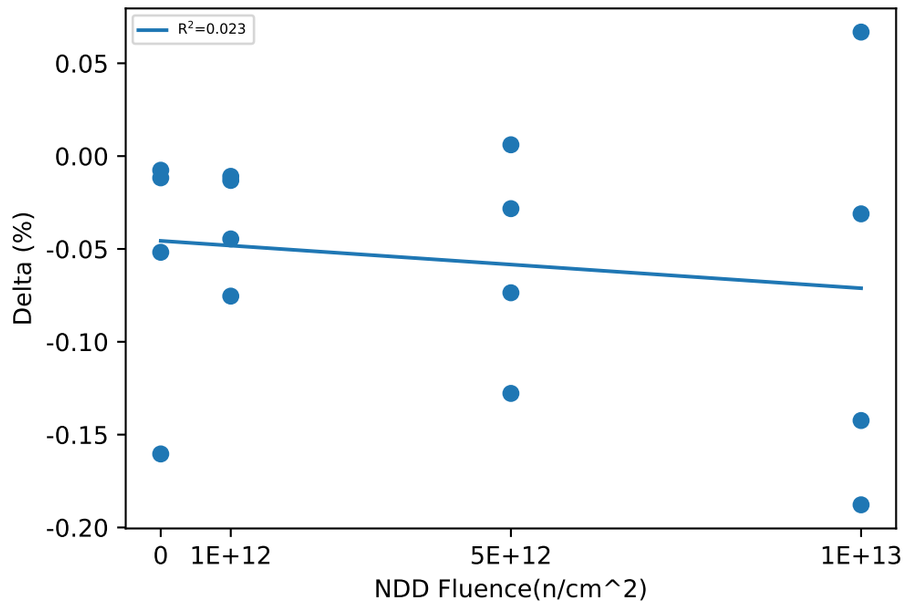
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.597	45.666	45.736	0.059788	45.569	45.61	45.709	0.066348	-0.1669	-0.0552	0.0212	0.08412
1e+12	45.586	45.628	45.657	0.030621	45.547	45.612	45.668	0.050607	-0.0394	-0.01525	0.0106	0.020555
5e+12	45.58	45.639	45.7	0.064189	45.514	45.583	45.694	0.077817	-0.1487	-0.0568	0.0046	0.070206
1e+13	45.489	45.647	45.803	0.13132	45.455	45.583	45.733	0.14071	-0.1579	-0.0644	0.0493	0.096822

Device Test: 27.31 LEVEL|DCL/OUT/12/12/0/0/5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

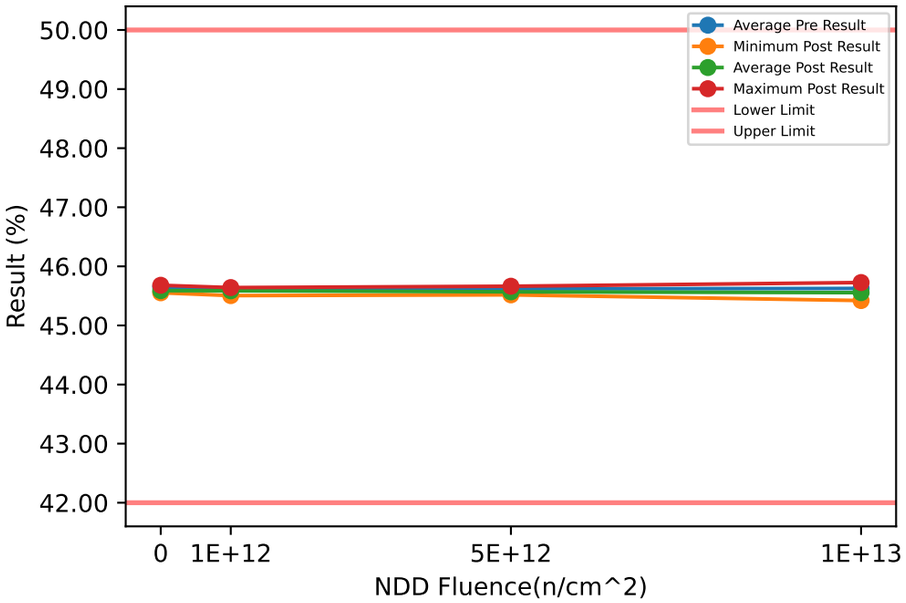
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.734	45.574	-0.1604
466	1e+12	NDD	45.654	45.609	-0.0446
762	0	CORRELATION	45.641	45.589	-0.0518
769	1e+12	NDD	45.665	45.654	-0.0109
887	1e+12	NDD	45.596	45.52	-0.0754
891	0	CORRELATION	45.581	45.57	-0.0117
927	1e+12	NDD	45.621	45.608	-0.0131
967	5e+12	NDD	45.679	45.685	0.0061
1204	1e+13	NDD	45.481	45.45	-0.0311
1284	1e+13	NDD	45.641	45.453	-0.1878
1292	5e+12	NDD	45.578	45.549	-0.0283
1364	1e+13	NDD	45.816	45.674	-0.1424
1383	5e+12	NDD	45.586	45.512	-0.0736
1388	5e+12	NDD	45.7	45.572	-0.1278
1427	1e+13	NDD	45.688	45.755	0.0668
1666	0	CORRELATION	45.719	45.711	-0.0076

Test Statistics (%)

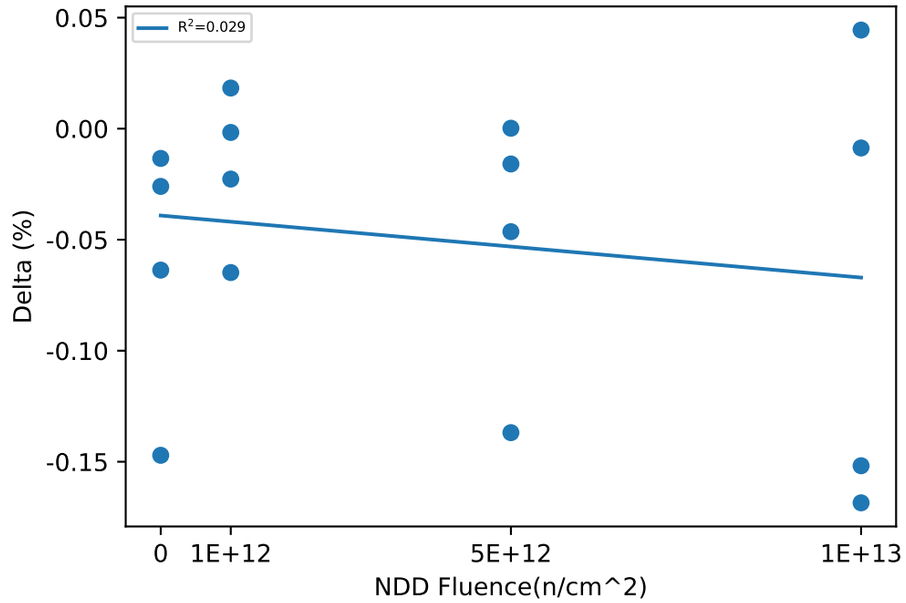
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.581	45.669	45.734	0.071192	45.57	45.611	45.711	0.067521	-0.1604	-0.057875	-0.0076	0.071199
1e+12	45.596	45.634	45.665	0.031476	45.52	45.598	45.654	0.05588	-0.0754	-0.036	-0.0109	0.030445
5e+12	45.578	45.636	45.7	0.062734	45.512	45.58	45.685	0.074409	-0.1278	-0.0559	0.0061	0.05799
1e+13	45.481	45.657	45.816	0.1384	45.45	45.583	45.755	0.15523	-0.1878	-0.073625	0.0668	0.11445

Device Test: 27.32 LEVEL|DCL/OUT/14/14/0/0/5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

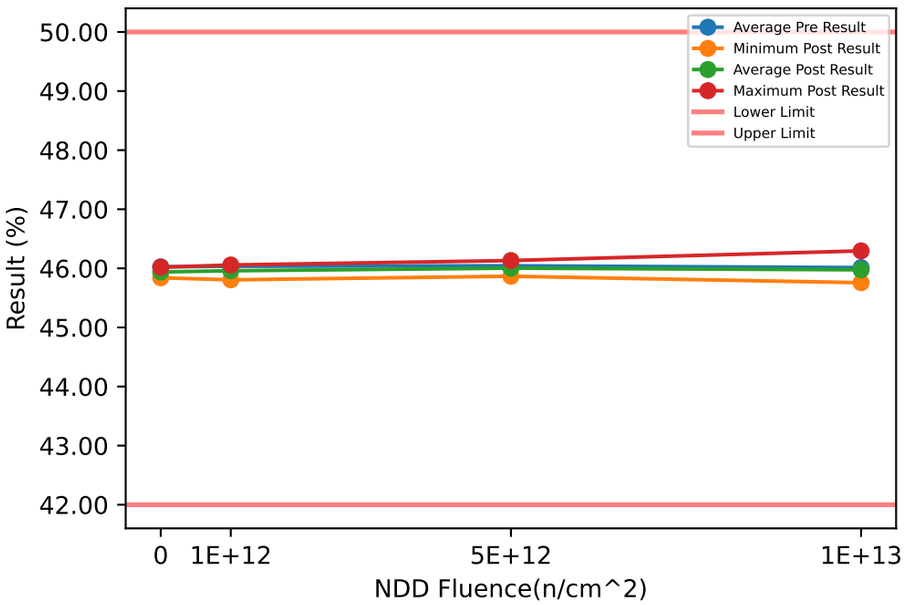
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.7	45.553	-0.1471
466	1e+12	NDD	45.622	45.599	-0.0227
762	0	CORRELATION	45.632	45.568	-0.0637
769	1e+12	NDD	45.642	45.641	-0.0017
887	1e+12	NDD	45.57	45.505	-0.0648
891	0	CORRELATION	45.568	45.555	-0.0134
927	1e+12	NDD	45.582	45.6	0.0183
967	5e+12	NDD	45.663	45.664	0.0002
1204	1e+13	NDD	45.441	45.432	-0.0087
1284	1e+13	NDD	45.59	45.421	-0.1685
1292	5e+12	NDD	45.545	45.53	-0.0159
1364	1e+13	NDD	45.792	45.641	-0.1518
1383	5e+12	NDD	45.564	45.518	-0.0464
1388	5e+12	NDD	45.701	45.564	-0.1369
1427	1e+13	NDD	45.681	45.726	0.0444
1666	0	CORRELATION	45.706	45.68	-0.026

Test Statistics (%)

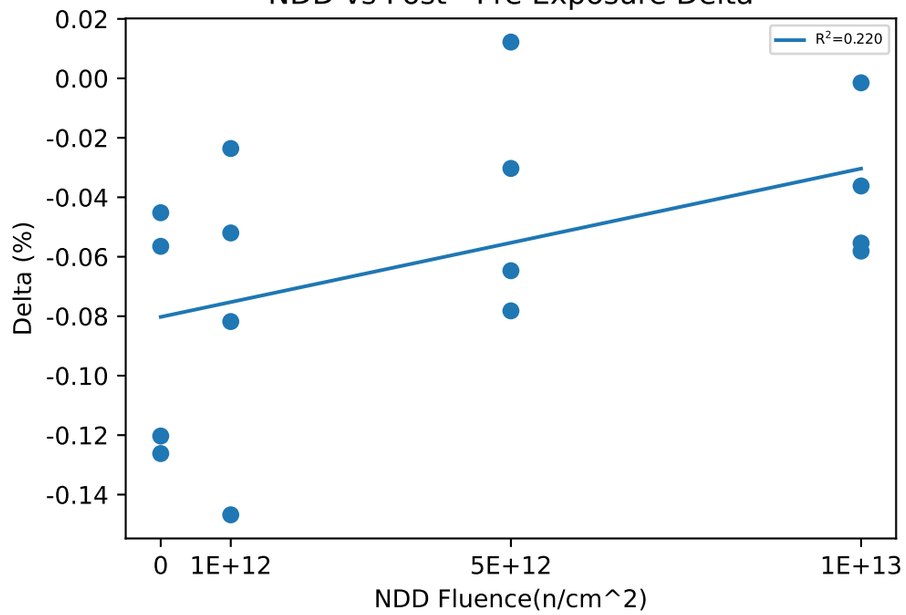
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.568	45.651	45.706	0.064773	45.553	45.589	45.68	0.060916	-0.1471	-0.06255	-0.0134	0.060282
1e+12	45.57	45.604	45.642	0.03381	45.505	45.586	45.641	0.057499	-0.0648	-0.017725	0.0183	0.035569
5e+12	45.545	45.618	45.701	0.075485	45.518	45.569	45.664	0.066227	-0.1369	-0.04975	0.0002	0.06123
1e+13	45.441	45.626	45.792	0.14887	45.421	45.555	45.726	0.1523	-0.1685	-0.07115	0.0444	0.10525

Device Test: 27.33 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

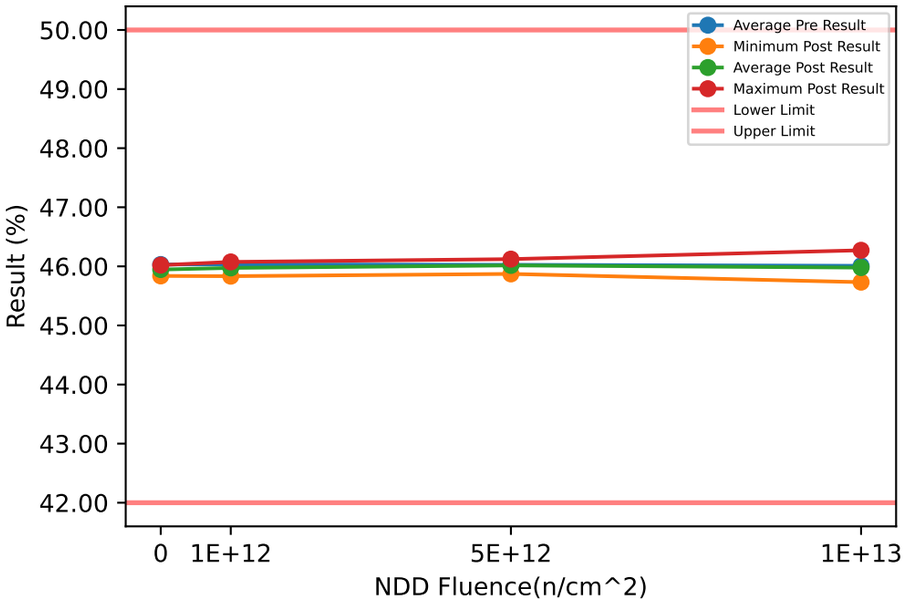
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.084	45.963	-0.1203
466	1e+12	NDD	45.953	45.806	-0.1468
762	0	CORRELATION	46.075	46.019	-0.0565
769	1e+12	NDD	46.003	45.922	-0.0818
887	1e+12	NDD	46.105	46.053	-0.052
891	0	CORRELATION	45.885	45.84	-0.0452
927	1e+12	NDD	46.08	46.057	-0.0236
967	5e+12	NDD	46.039	45.961	-0.0782
1204	1e+13	NDD	45.811	45.809	-0.0015
1284	1e+13	NDD	45.794	45.757	-0.0362
1292	5e+12	NDD	45.897	45.866	-0.0303
1364	1e+13	NDD	46.353	46.295	-0.0581
1383	5e+12	NDD	46.041	46.054	0.0122
1388	5e+12	NDD	46.197	46.132	-0.0647
1427	1e+13	NDD	46.093	46.038	-0.0554
1666	0	CORRELATION	46.059	45.933	-0.1262

Test Statistics (%)

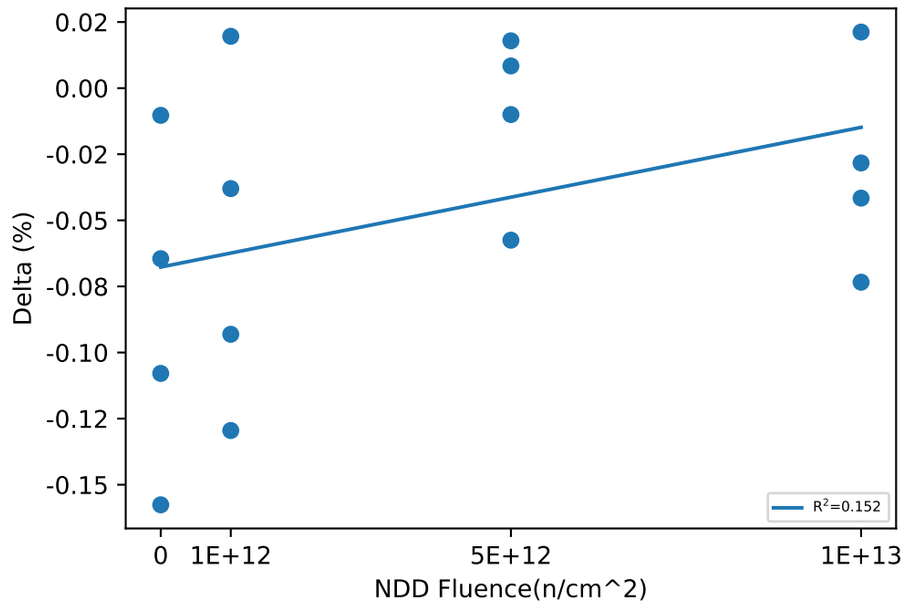
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.885	46.026	46.084	0.094281	45.84	45.939	46.019	0.07485	-0.1262	-0.08705	-0.0452	0.042123
1e+12	45.953	46.035	46.105	0.070007	45.806	45.959	46.057	0.11999	-0.1468	-0.07605	-0.0236	0.052814
5e+12	45.897	46.043	46.197	0.12261	45.866	46.003	46.132	0.11502	-0.0782	-0.04025	0.0122	0.040365
1e+13	45.794	46.013	46.353	0.26542	45.757	45.975	46.295	0.24588	-0.0581	-0.0378	-0.0015	0.02609

Device Test: 27.34 LEVEL|WRST_MAX/OUT/5/5/0/0/5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

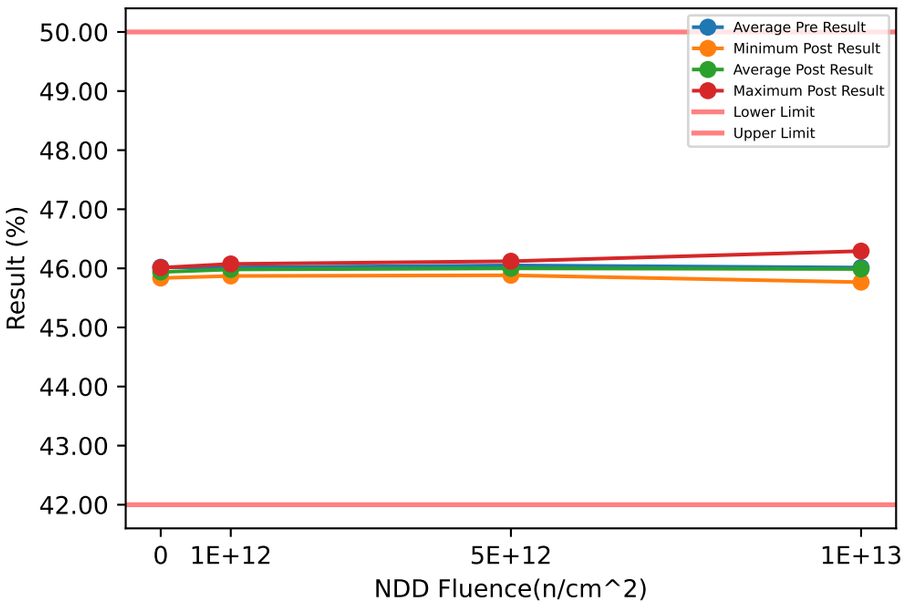
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.081	45.973	-0.1079
466	1e+12	NDD	45.963	45.834	-0.1295
762	0	CORRELATION	46.085	46.02	-0.0645
769	1e+12	NDD	46.034	45.941	-0.0931
887	1e+12	NDD	46.113	46.075	-0.038
891	0	CORRELATION	45.848	45.838	-0.0103
927	1e+12	NDD	46.024	46.044	0.0196
967	5e+12	NDD	46.001	46.009	0.0084
1204	1e+13	NDD	45.842	45.8	-0.0416
1284	1e+13	NDD	45.806	45.732	-0.0734
1292	5e+12	NDD	45.882	45.872	-0.01
1364	1e+13	NDD	46.3	46.272	-0.0283
1383	5e+12	NDD	46.041	46.059	0.0179
1388	5e+12	NDD	46.18	46.122	-0.0575
1427	1e+13	NDD	46.089	46.11	0.0212
1666	0	CORRELATION	46.11	45.953	-0.1576

Test Statistics (%)

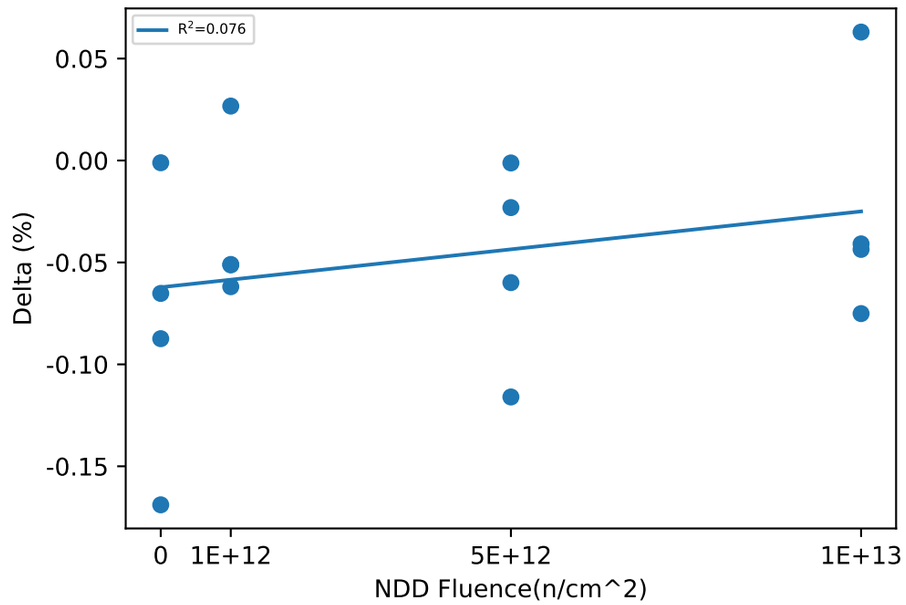
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.848	46.031	46.11	0.12261	45.838	45.946	46.02	0.077478	-0.1576	-0.085075	-0.0103	0.062704
1e+12	45.963	46.034	46.113	0.061496	45.834	45.973	46.075	0.10936	-0.1295	-0.06025	0.0196	0.065181
5e+12	45.882	46.026	46.18	0.12287	45.872	46.016	46.122	0.10642	-0.0575	-0.0103	0.0179	0.03353
1e+13	45.806	46.009	46.3	0.23119	45.732	45.979	46.272	0.2554	-0.0734	-0.030525	0.0212	0.039333

Device Test: 27.35 LEVEL|WRST_MAX/OUT/12/12/0/0/5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

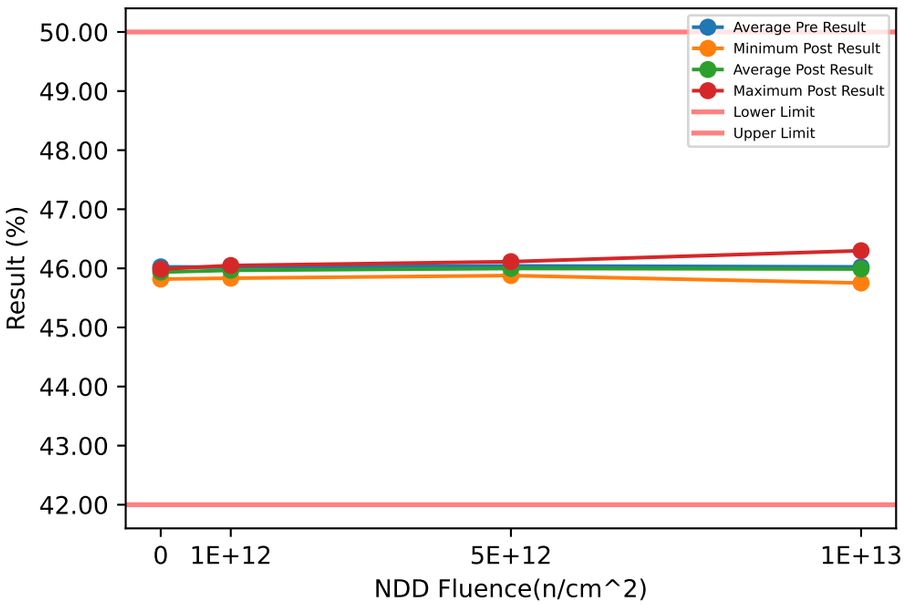
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.111	45.942	-0.1689
466	1e+12	NDD	45.922	45.871	-0.051
762	0	CORRELATION	46.013	46.011	-0.0011
769	1e+12	NDD	45.995	45.944	-0.0512
887	1e+12	NDD	46.048	46.074	0.0267
891	0	CORRELATION	45.901	45.836	-0.0652
927	1e+12	NDD	46.096	46.034	-0.0619
967	5e+12	NDD	46.05	45.99	-0.0599
1204	1e+13	NDD	45.839	45.798	-0.0409
1284	1e+13	NDD	45.81	45.767	-0.0436
1292	5e+12	NDD	45.906	45.883	-0.0231
1364	1e+13	NDD	46.367	46.292	-0.0751
1383	5e+12	NDD	46.006	46.005	-0.0012
1388	5e+12	NDD	46.236	46.12	-0.116
1427	1e+13	NDD	46.036	46.099	0.063
1666	0	CORRELATION	46.051	45.963	-0.0874

Test Statistics (%)

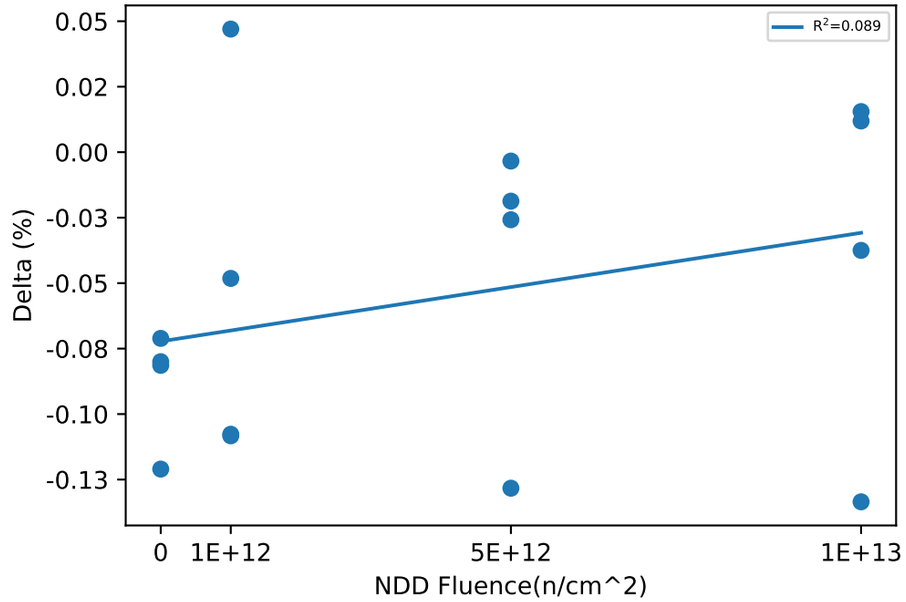
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.901	46.019	46.111	0.088367	45.836	45.938	46.011	0.074016	-0.1689	-0.08065	-0.0011	0.069283
1e+12	45.922	46.015	46.096	0.074547	45.871	45.981	46.074	0.09124	-0.0619	-0.03435	0.0267	0.041017
5e+12	45.906	46.05	46.236	0.13855	45.883	45.999	46.12	0.097363	-0.116	-0.05005	-0.0012	0.050196
1e+13	45.81	46.013	46.367	0.25632	45.767	45.989	46.292	0.25144	-0.0751	-0.02415	0.063	0.060138

Device Test: 27.36 LEVEL|WRST_MAX/OUT/14/14/0/0/5/100kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

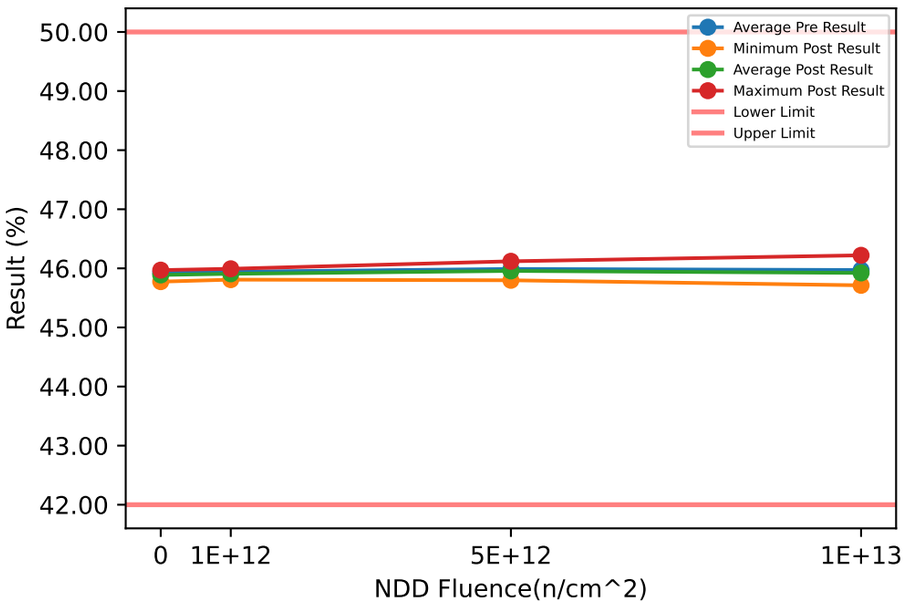
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.107	45.986	-0.121
466	1e+12	NDD	45.941	45.833	-0.1083
762	0	CORRELATION	46.059	45.978	-0.0814
769	1e+12	NDD	45.908	45.955	0.047
887	1e+12	NDD	46.096	46.048	-0.0482
891	0	CORRELATION	45.898	45.818	-0.08
927	1e+12	NDD	46.137	46.029	-0.1077
967	5e+12	NDD	45.986	45.983	-0.0034
1204	1e+13	NDD	45.874	45.837	-0.0375
1284	1e+13	NDD	45.886	45.752	-0.1335
1292	5e+12	NDD	45.897	45.878	-0.0187
1364	1e+13	NDD	46.283	46.298	0.0155
1383	5e+12	NDD	46.041	46.015	-0.0258
1388	5e+12	NDD	46.242	46.113	-0.1283
1427	1e+13	NDD	46.057	46.069	0.0119
1666	0	CORRELATION	46.035	45.964	-0.0711

Test Statistics (%)

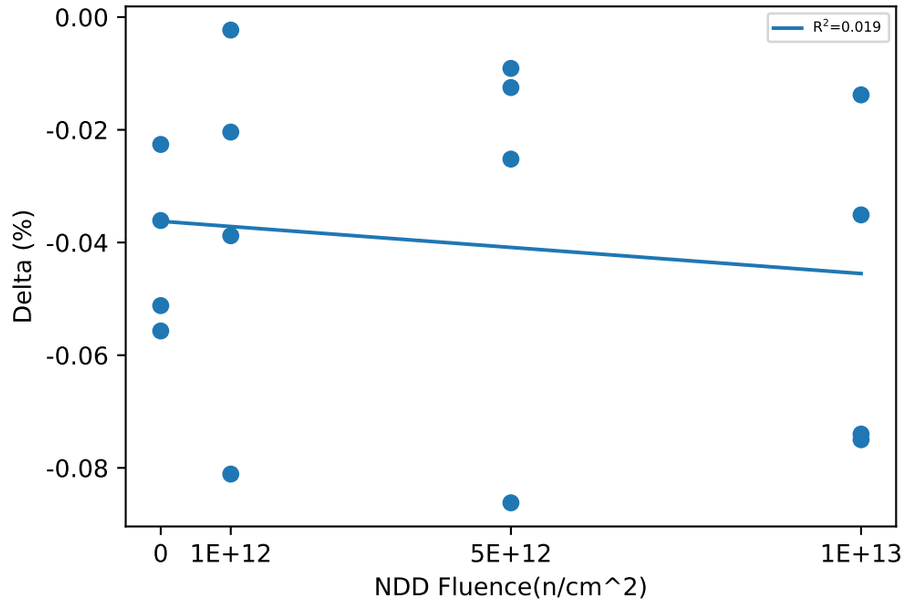
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.898	46.025	46.107	0.089585	45.818	45.937	45.986	0.079374	-0.121	-0.088375	-0.0711	0.022223
1e+12	45.908	46.021	46.137	0.11277	45.833	45.966	46.048	0.097421	-0.1083	-0.0543	0.047	0.073181
5e+12	45.897	46.041	46.242	0.14613	45.878	45.997	46.113	0.09698	-0.1283	-0.04405	-0.0034	0.056939
1e+13	45.874	46.025	46.283	0.19119	45.752	45.989	46.298	0.24588	-0.1335	-0.0359	0.0155	0.069415

Device Test: 27.37 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

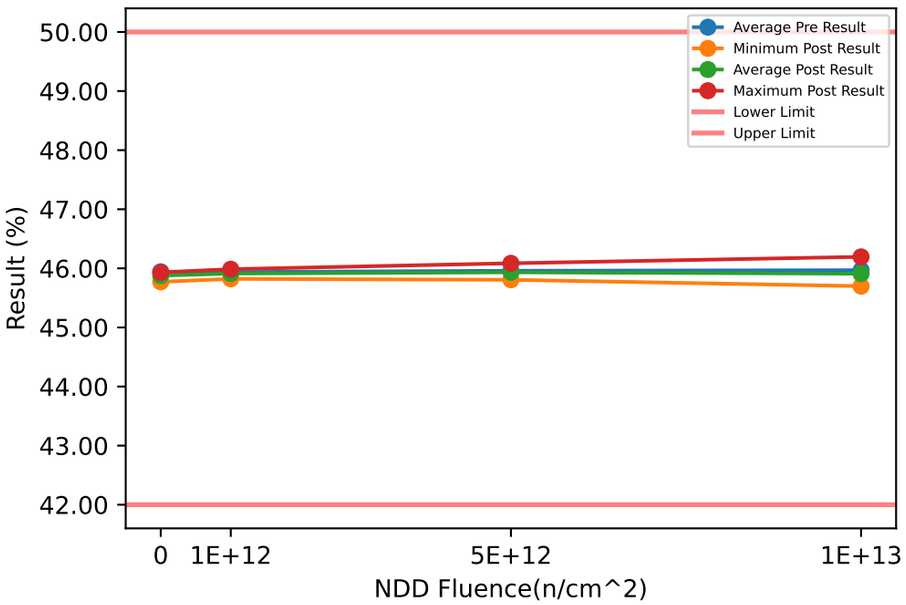
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.006	45.97	-0.0361
466	1e+12	NDD	45.89	45.809	-0.0811
762	0	CORRELATION	45.948	45.925	-0.0226
769	1e+12	NDD	45.875	45.873	-0.0023
887	1e+12	NDD	46.031	45.993	-0.0388
891	0	CORRELATION	45.826	45.775	-0.0512
927	1e+12	NDD	45.977	45.956	-0.0204
967	5e+12	NDD	46.016	45.93	-0.0862
1204	1e+13	NDD	45.818	45.744	-0.074
1284	1e+13	NDD	45.788	45.713	-0.075
1292	5e+12	NDD	45.823	45.798	-0.0252
1364	1e+13	NDD	46.234	46.221	-0.0138
1383	5e+12	NDD	45.991	45.978	-0.0125
1388	5e+12	NDD	46.129	46.12	-0.0091
1427	1e+13	NDD	46.048	46.013	-0.0351
1666	0	CORRELATION	45.938	45.882	-0.0557

Test Statistics (%)

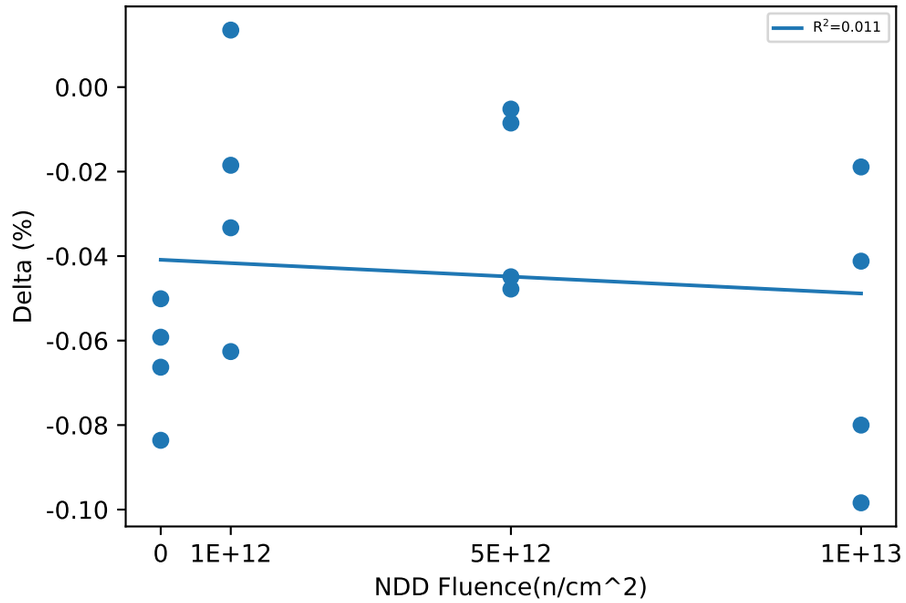
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.826	45.93	46.006	0.075203	45.775	45.888	45.97	0.08353	-0.0557	-0.0414	-0.0226	0.015078
1e+12	45.875	45.943	46.031	0.073977	45.809	45.908	45.993	0.082871	-0.0811	-0.03565	-0.0023	0.033766
5e+12	45.823	45.99	46.129	0.12611	45.798	45.956	46.12	0.13274	-0.0862	-0.03325	-0.0091	0.035974
1e+13	45.788	45.972	46.234	0.20991	45.713	45.922	46.221	0.23998	-0.075	-0.049475	-0.0138	0.030179

Device Test: 27.38 LEVEL|WRST_MAX/OUT/5/5/0/0/5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

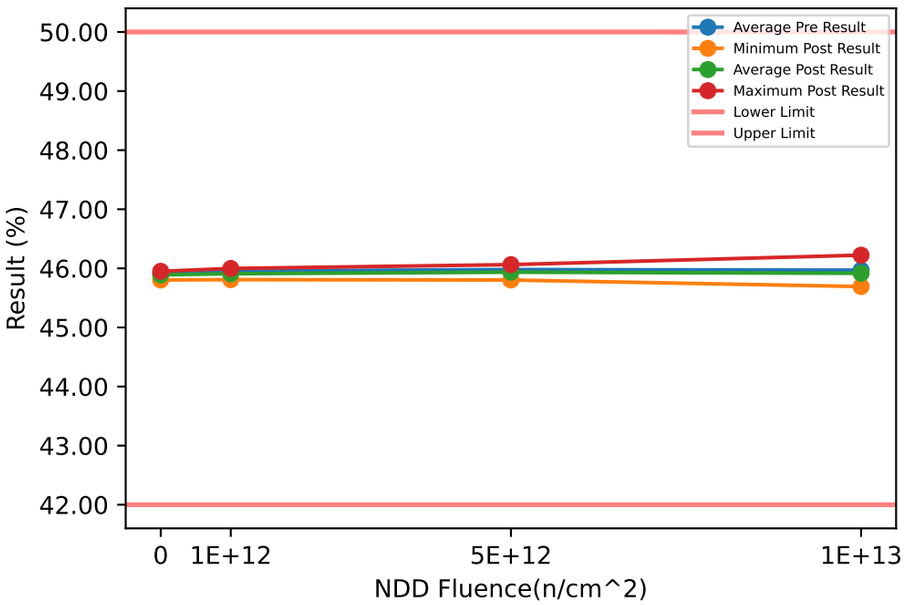
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.016	45.932	-0.0836
466	1e+12	NDD	45.809	45.822	0.0135
762	0	CORRELATION	45.974	45.914	-0.0592
769	1e+12	NDD	45.936	45.873	-0.0626
887	1e+12	NDD	46.019	45.986	-0.0333
891	0	CORRELATION	45.837	45.771	-0.0663
927	1e+12	NDD	45.986	45.968	-0.0185
967	5e+12	NDD	45.915	45.906	-0.0085
1204	1e+13	NDD	45.778	45.737	-0.0412
1284	1e+13	NDD	45.797	45.698	-0.0984
1292	5e+12	NDD	45.854	45.806	-0.0478
1364	1e+13	NDD	46.275	46.194	-0.08
1383	5e+12	NDD	45.977	45.932	-0.0449
1388	5e+12	NDD	46.091	46.086	-0.0052
1427	1e+13	NDD	46.027	46.008	-0.0189
1666	0	CORRELATION	45.939	45.889	-0.0501

Test Statistics (%)

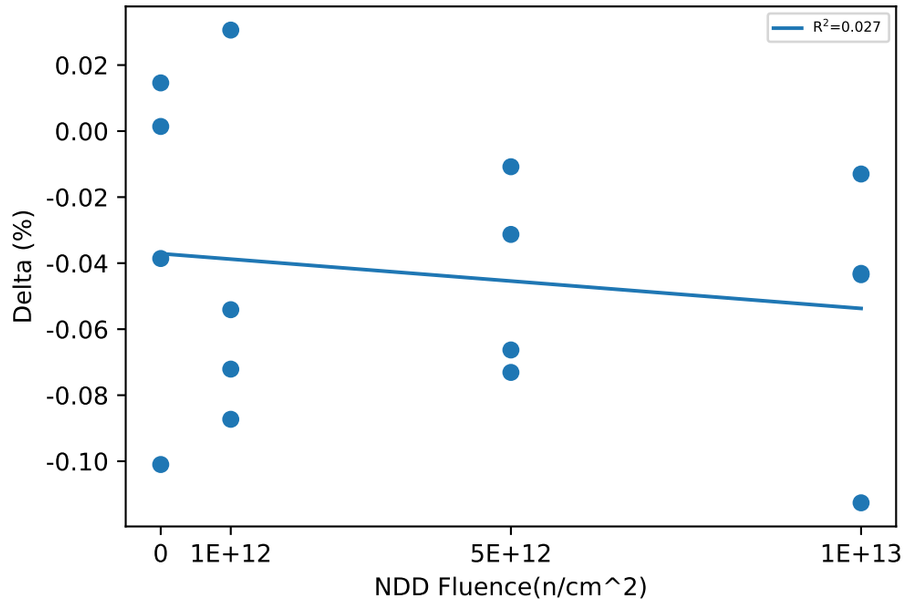
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.837	45.942	46.016	0.076223	45.771	45.877	45.932	0.07265	-0.0836	-0.0648	-0.0501	0.014179
1e+12	45.809	45.937	46.019	0.092532	45.822	45.912	45.986	0.077757	-0.0626	-0.025225	0.0135	0.031659
5e+12	45.854	45.959	46.091	0.10106	45.806	45.933	46.086	0.11552	-0.0478	-0.0266	-0.0052	0.022876
1e+13	45.778	45.969	46.275	0.23304	45.698	45.909	46.194	0.23484	-0.0984	-0.059625	-0.0189	0.036132

Device Test: 27.39 LEVEL|WRST_MAX/OUT/12/12/0/0/5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

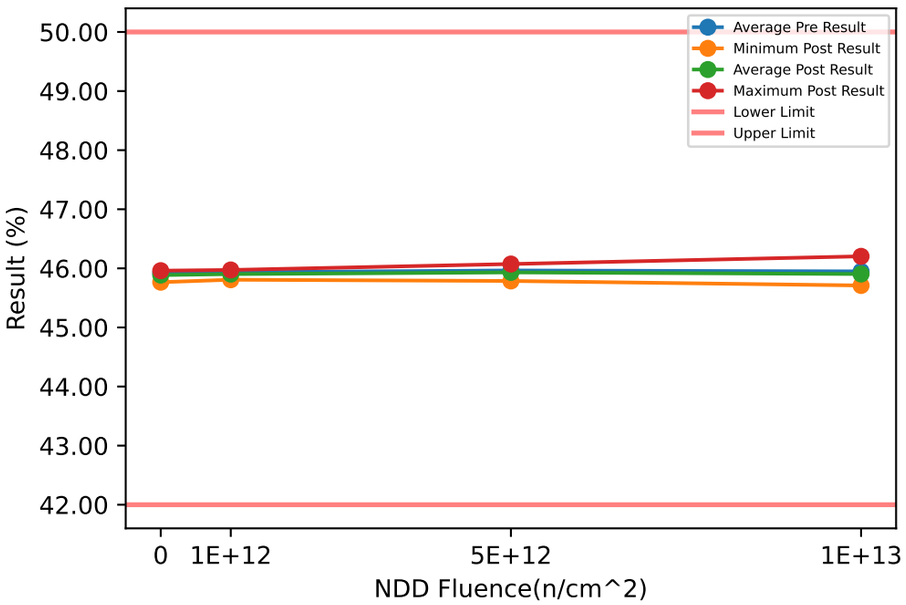
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.949	45.95	0.0014
466	1e+12	NDD	45.896	45.809	-0.0873
762	0	CORRELATION	45.961	45.922	-0.0386
769	1e+12	NDD	45.92	45.866	-0.0541
887	1e+12	NDD	46.034	45.962	-0.0721
891	0	CORRELATION	45.788	45.803	0.0146
927	1e+12	NDD	45.967	45.998	0.0306
967	5e+12	NDD	45.983	45.917	-0.0663
1204	1e+13	NDD	45.783	45.74	-0.0431
1284	1e+13	NDD	45.804	45.692	-0.1126
1292	5e+12	NDD	45.813	45.803	-0.0108
1364	1e+13	NDD	46.267	46.223	-0.0435
1383	5e+12	NDD	45.987	45.956	-0.0313
1388	5e+12	NDD	46.136	46.063	-0.0731
1427	1e+13	NDD	46.022	46.008	-0.013
1666	0	CORRELATION	45.981	45.88	-0.101

Test Statistics (%)

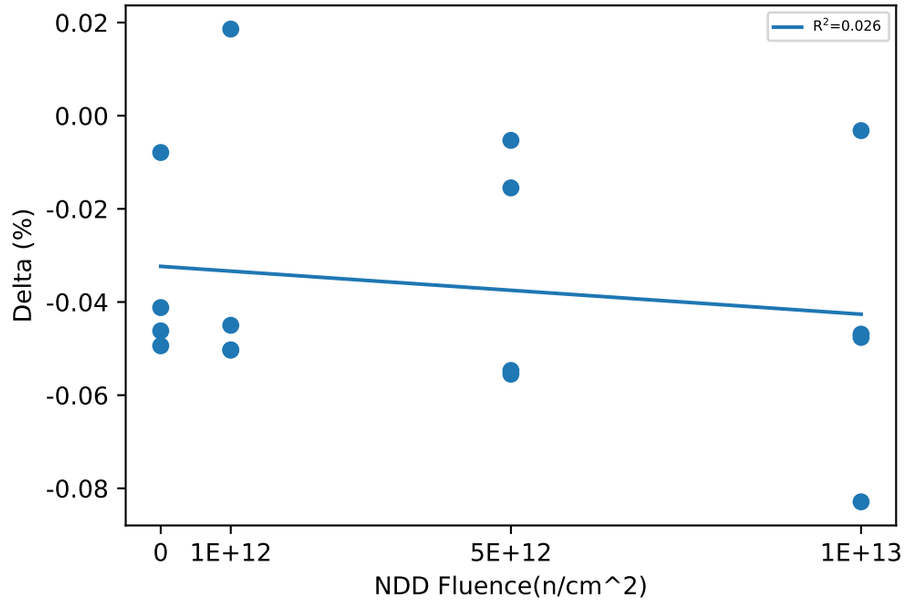
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.788	45.92	45.981	0.088772	45.803	45.889	45.95	0.06413	-0.101	-0.0309	0.0146	0.051919
1e+12	45.896	45.954	46.034	0.060957	45.809	45.909	45.998	0.08692	-0.0873	-0.045725	0.0306	0.052662
5e+12	45.813	45.98	46.136	0.13185	45.803	45.935	46.063	0.10743	-0.0731	-0.045375	-0.0108	0.02944
1e+13	45.783	45.969	46.267	0.22588	45.692	45.916	46.223	0.24782	-0.1126	-0.05305	-0.013	0.042192

Device Test: 27.40 LEVEL|WRST_MAX/OUT/14/14/0/0/5/200kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

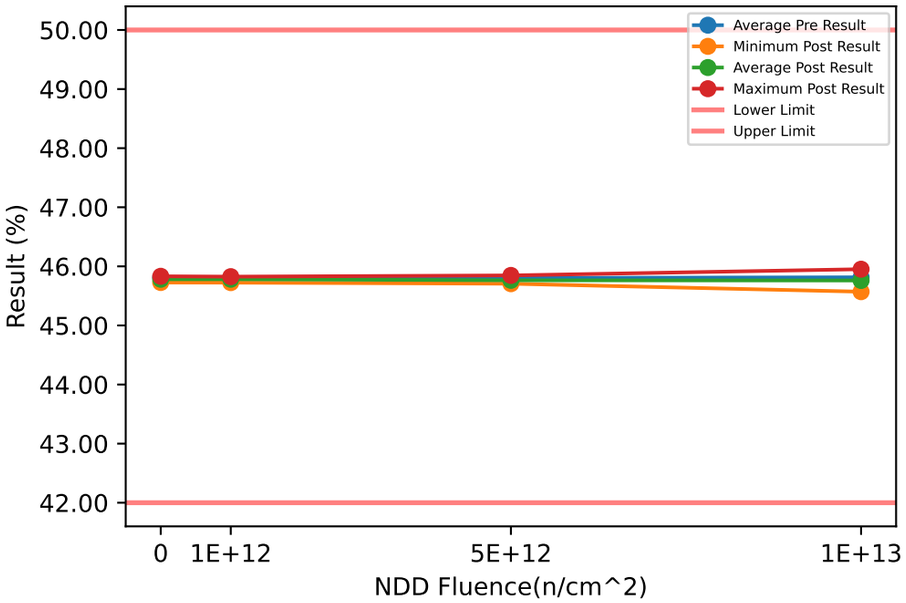
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	46.002	45.961	-0.0412
466	1e+12	NDD	45.852	45.807	-0.045
762	0	CORRELATION	45.972	45.926	-0.0462
769	1e+12	NDD	45.921	45.87	-0.0503
887	1e+12	NDD	46.01	45.96	-0.0503
891	0	CORRELATION	45.773	45.766	-0.0079
927	1e+12	NDD	45.954	45.973	0.0186
967	5e+12	NDD	45.959	45.904	-0.0547
1204	1e+13	NDD	45.759	45.712	-0.0469
1284	1e+13	NDD	45.793	45.71	-0.0829
1292	5e+12	NDD	45.802	45.786	-0.0155
1364	1e+13	NDD	46.206	46.203	-0.0032
1383	5e+12	NDD	45.967	45.962	-0.0053
1388	5e+12	NDD	46.129	46.073	-0.0555
1427	1e+13	NDD	46.038	45.99	-0.0476
1666	0	CORRELATION	45.941	45.892	-0.0494

Test Statistics (%)

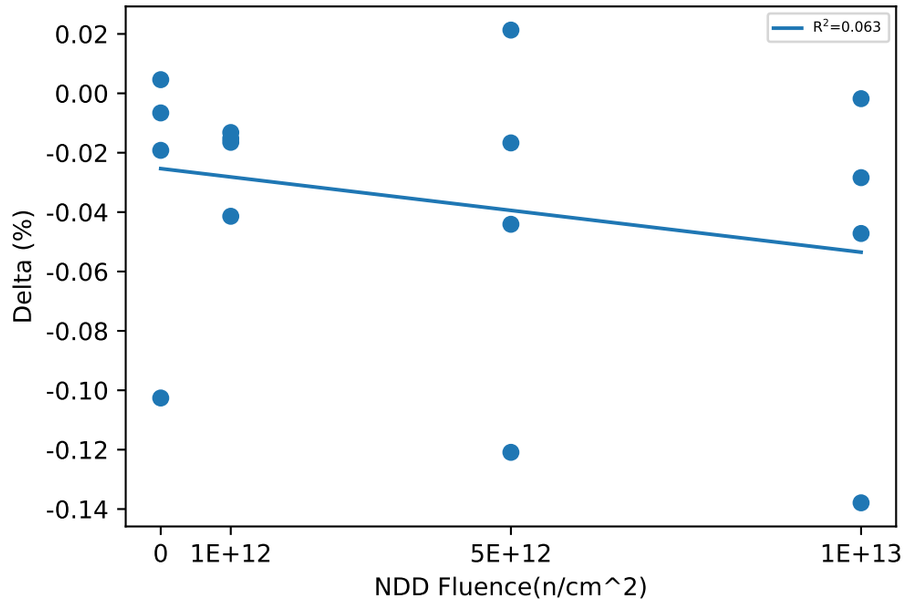
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.773	45.922	46.002	0.10211	45.766	45.886	45.961	0.085001	-0.0494	-0.036175	-0.0079	0.01915
1e+12	45.852	45.934	46.01	0.065974	45.807	45.903	45.973	0.078107	-0.0503	-0.03175	0.0186	0.03366
5e+12	45.802	45.964	46.129	0.13342	45.786	45.931	46.073	0.11941	-0.0555	-0.03275	-0.0053	0.026143
1e+13	45.759	45.949	46.206	0.21176	45.71	45.904	46.203	0.23897	-0.0829	-0.04515	-0.0032	0.032629

Device Test: 27.41 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

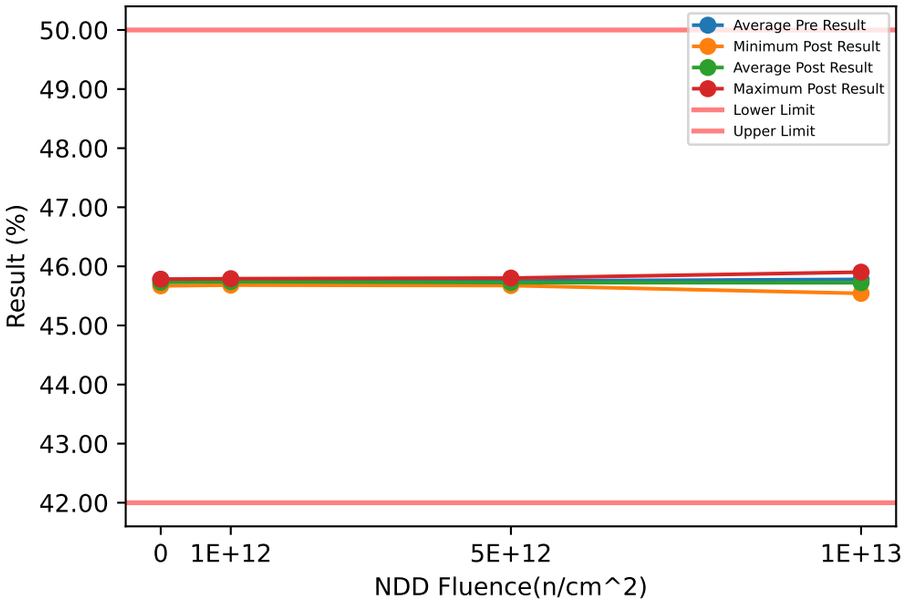
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.894	45.791	-0.1026
466	1e+12	NDD	45.773	45.758	-0.0152
762	0	CORRELATION	45.784	45.777	-0.0066
769	1e+12	NDD	45.738	45.724	-0.0132
887	1e+12	NDD	45.861	45.819	-0.0414
891	0	CORRELATION	45.722	45.726	0.0046
927	1e+12	NDD	45.842	45.826	-0.0165
967	5e+12	NDD	45.766	45.787	0.0213
1204	1e+13	NDD	45.618	45.571	-0.0472
1284	1e+13	NDD	45.77	45.632	-0.1379
1292	5e+12	NDD	45.75	45.706	-0.0441
1364	1e+13	NDD	45.98	45.952	-0.0284
1383	5e+12	NDD	45.731	45.715	-0.0167
1388	5e+12	NDD	45.967	45.846	-0.1209
1427	1e+13	NDD	45.891	45.889	-0.0018
1666	0	CORRELATION	45.851	45.832	-0.0192

Test Statistics (%)

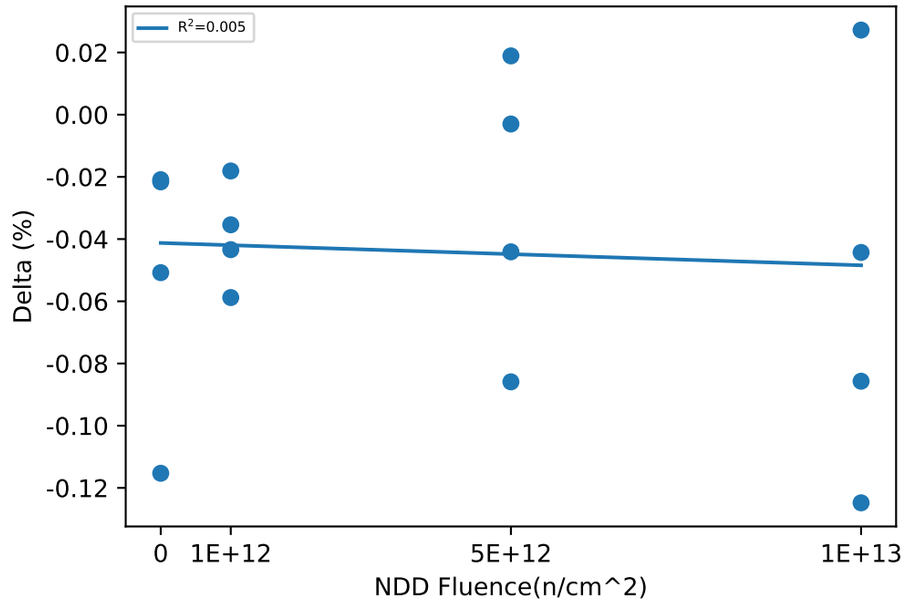
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.722	45.813	45.894	0.075705	45.726	45.782	45.832	0.043567	-0.1026	-0.03095	0.0046	0.048746
1e+12	45.738	45.803	45.861	0.057906	45.724	45.782	45.826	0.049039	-0.0414	-0.021575	-0.0132	0.013286
5e+12	45.731	45.804	45.967	0.10998	45.706	45.764	45.846	0.066102	-0.1209	-0.0401	0.0213	0.060172
1e+13	45.618	45.815	45.98	0.15685	45.571	45.761	45.952	0.18762	-0.1379	-0.053825	-0.0018	0.059064

Device Test: 27.42 LEVEL|WRST_MAX/OUT/5/5/0/0/5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

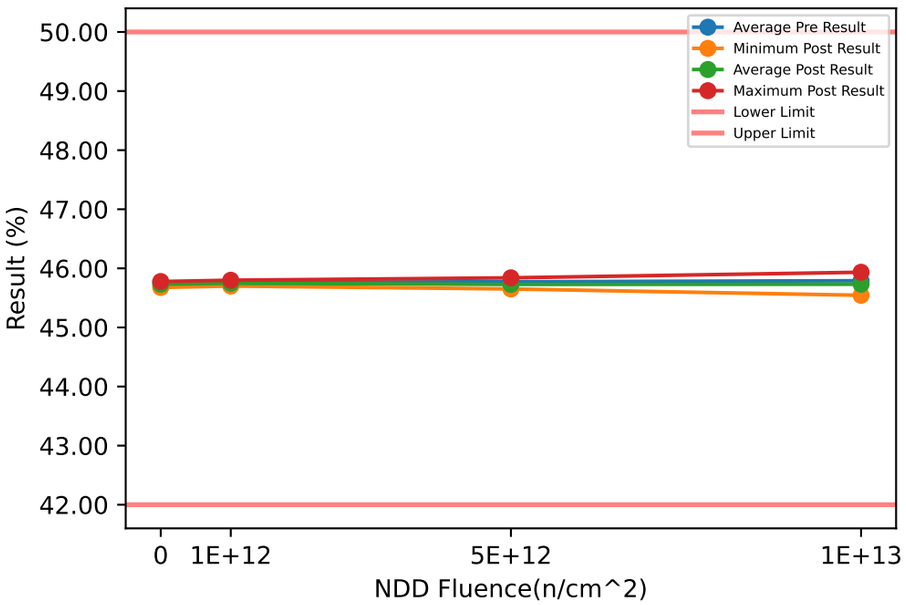
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.867	45.751	-0.1153
466	1e+12	NDD	45.761	45.726	-0.0354
762	0	CORRELATION	45.763	45.712	-0.0508
769	1e+12	NDD	45.741	45.682	-0.0588
887	1e+12	NDD	45.807	45.763	-0.0434
891	0	CORRELATION	45.691	45.67	-0.0209
927	1e+12	NDD	45.809	45.791	-0.0181
967	5e+12	NDD	45.714	45.733	0.0189
1204	1e+13	NDD	45.587	45.543	-0.0443
1284	1e+13	NDD	45.711	45.586	-0.1248
1292	5e+12	NDD	45.692	45.689	-0.003
1364	1e+13	NDD	45.988	45.902	-0.0857
1383	5e+12	NDD	45.719	45.675	-0.0441
1388	5e+12	NDD	45.887	45.801	-0.0859
1427	1e+13	NDD	45.831	45.858	0.0272
1666	0	CORRELATION	45.803	45.781	-0.0216

Test Statistics (%)

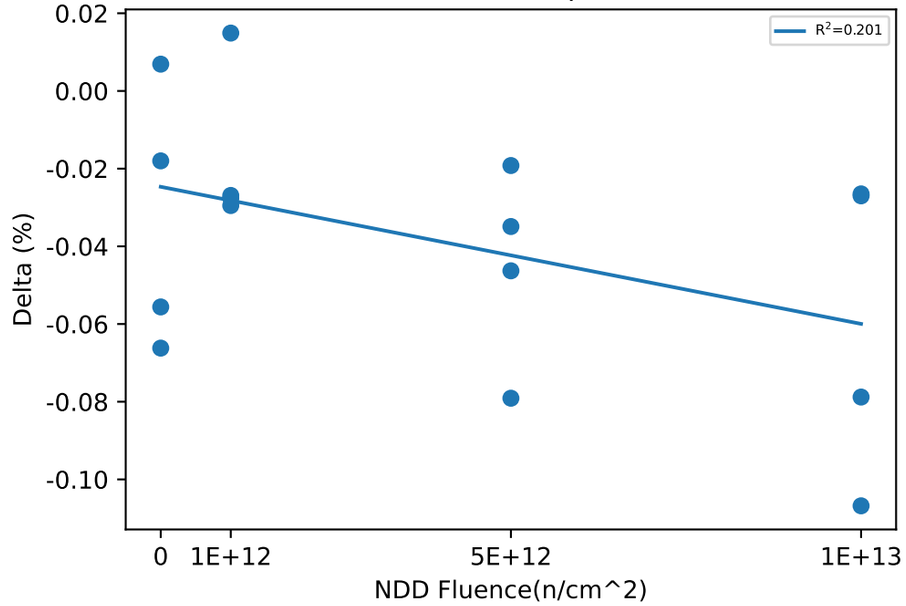
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.691	45.781	45.867	0.073622	45.67	45.729	45.781	0.048332	-0.1153	-0.05215	-0.0209	0.044346
1e+12	45.741	45.78	45.809	0.033908	45.682	45.741	45.791	0.047307	-0.0588	-0.038925	-0.0181	0.016943
5e+12	45.692	45.753	45.887	0.090336	45.675	45.725	45.801	0.057028	-0.0859	-0.028525	0.0189	0.046315
1e+13	45.587	45.779	45.988	0.17103	45.543	45.722	45.902	0.184	-0.1248	-0.0569	0.0272	0.064991

Device Test: 27.43 LEVEL|WRST_MAX/OUT/12/12/0/0/5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

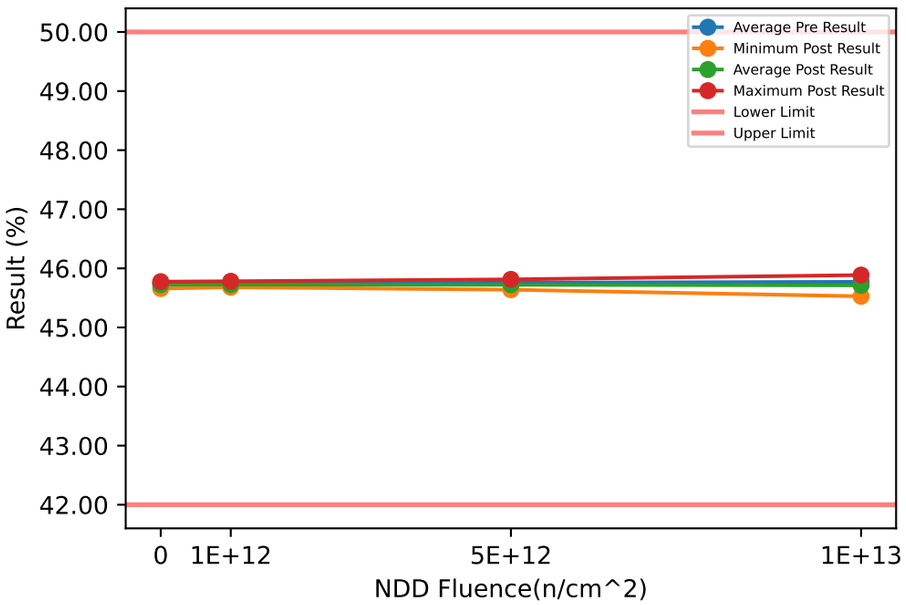
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.82	45.754	-0.0662
466	1e+12	NDD	45.739	45.712	-0.0269
762	0	CORRELATION	45.773	45.718	-0.0556
769	1e+12	NDD	45.73	45.7	-0.0295
887	1e+12	NDD	45.803	45.775	-0.0276
891	0	CORRELATION	45.669	45.676	0.0069
927	1e+12	NDD	45.784	45.799	0.0149
967	5e+12	NDD	45.815	45.736	-0.0791
1204	1e+13	NDD	45.571	45.544	-0.0265
1284	1e+13	NDD	45.703	45.596	-0.1068
1292	5e+12	NDD	45.67	45.651	-0.0192
1364	1e+13	NDD	46.013	45.934	-0.0788
1383	5e+12	NDD	45.72	45.685	-0.0349
1388	5e+12	NDD	45.886	45.84	-0.0463
1427	1e+13	NDD	45.877	45.85	-0.027
1666	0	CORRELATION	45.795	45.777	-0.018

Test Statistics (%)

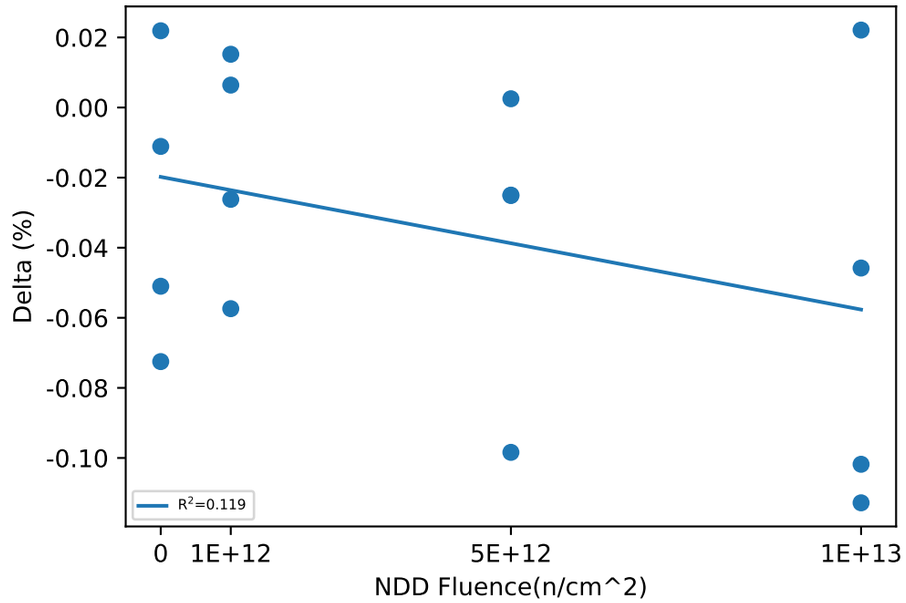
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.669	45.764	45.82	0.066153	45.676	45.731	45.777	0.043995	-0.0662	-0.033225	0.0069	0.033812
1e+12	45.73	45.764	45.803	0.035171	45.7	45.747	45.799	0.047982	-0.0295	-0.017275	0.0149	0.021478
5e+12	45.67	45.773	45.886	0.096297	45.651	45.728	45.84	0.082096	-0.0791	-0.044875	-0.0192	0.025378
1e+13	45.571	45.791	46.013	0.19404	45.544	45.731	45.934	0.19023	-0.1068	-0.059775	-0.0265	0.039811

Device Test: 27.44 LEVEL|WRST_MAX/OUT/14/14/0/0/5/500kHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

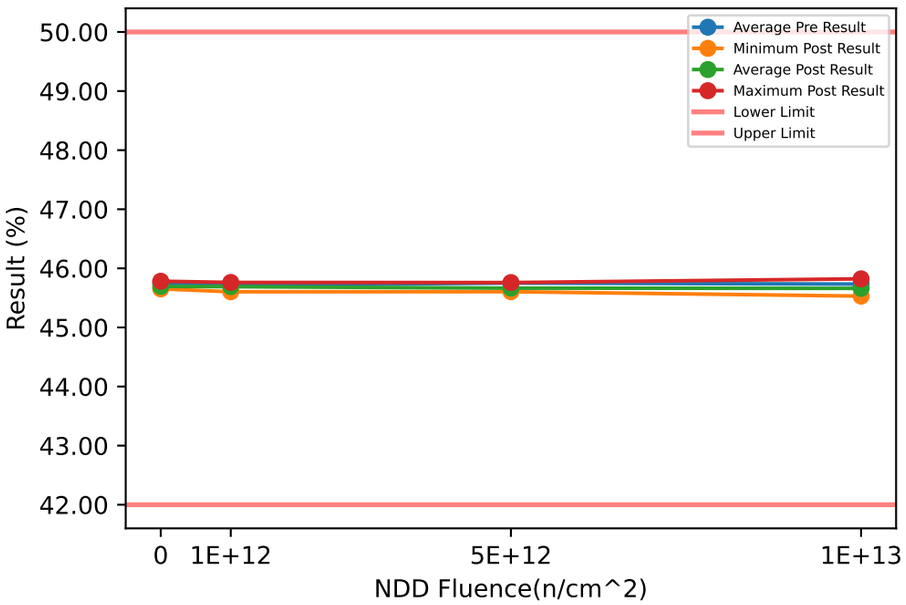
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.804	45.753	-0.051
466	1e+12	NDD	45.7	45.706	0.0064
762	0	CORRELATION	45.778	45.706	-0.0725
769	1e+12	NDD	45.706	45.68	-0.0262
887	1e+12	NDD	45.788	45.731	-0.0574
891	0	CORRELATION	45.669	45.658	-0.0111
927	1e+12	NDD	45.766	45.782	0.0152
967	5e+12	NDD	45.761	45.736	-0.025
1204	1e+13	NDD	45.573	45.527	-0.0458
1284	1e+13	NDD	45.682	45.57	-0.1128
1292	5e+12	NDD	45.663	45.638	-0.0251
1364	1e+13	NDD	45.988	45.886	-0.1018
1383	5e+12	NDD	45.694	45.697	0.0025
1388	5e+12	NDD	45.912	45.813	-0.0984
1427	1e+13	NDD	45.844	45.866	0.0221
1666	0	CORRELATION	45.753	45.775	0.0219

Test Statistics (%)

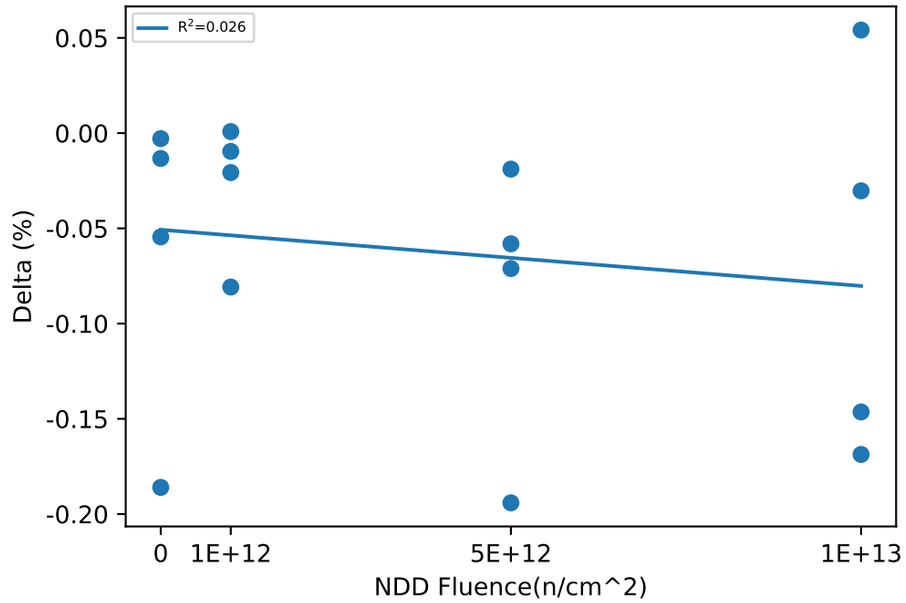
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.669	45.751	45.804	0.058532	45.658	45.723	45.775	0.052086	-0.0725	-0.028175	0.0219	0.041971
1e+12	45.7	45.74	45.788	0.043946	45.68	45.725	45.782	0.043199	-0.0574	-0.0155	0.0152	0.033127
5e+12	45.663	45.757	45.912	0.11058	45.638	45.721	45.813	0.073454	-0.0984	-0.0365	0.0025	0.043262
1e+13	45.573	45.772	45.988	0.18188	45.527	45.712	45.886	0.19001	-0.1128	-0.059575	0.0221	0.06185

Device Test: 27.45 LEVEL|WRST_MAX/OUT/4.5/4.5/0/0/4.5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

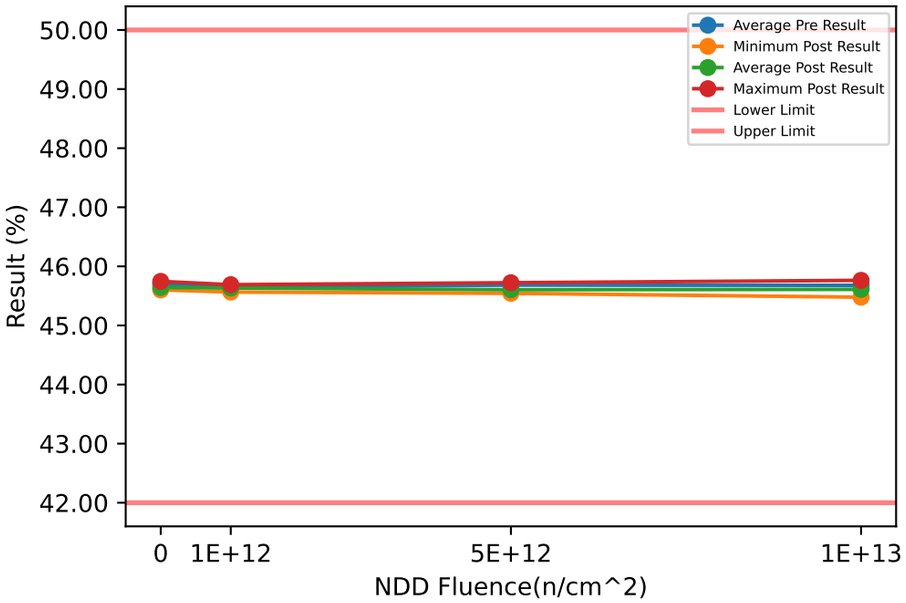
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.839	45.653	-0.186
466	1e+12	NDD	45.724	45.714	-0.0096
762	0	CORRELATION	45.707	45.652	-0.0545
769	1e+12	NDD	45.761	45.761	0.0008
887	1e+12	NDD	45.684	45.604	-0.0808
891	0	CORRELATION	45.693	45.69	-0.0029
927	1e+12	NDD	45.7	45.679	-0.0207
967	5e+12	NDD	45.817	45.759	-0.0581
1204	1e+13	NDD	45.582	45.552	-0.0303
1284	1e+13	NDD	45.699	45.53	-0.1687
1292	5e+12	NDD	45.666	45.648	-0.0189
1364	1e+13	NDD	45.885	45.739	-0.1464
1383	5e+12	NDD	45.676	45.605	-0.0711
1388	5e+12	NDD	45.842	45.648	-0.1941
1427	1e+13	NDD	45.769	45.823	0.0541
1666	0	CORRELATION	45.796	45.782	-0.0133

Test Statistics (%)

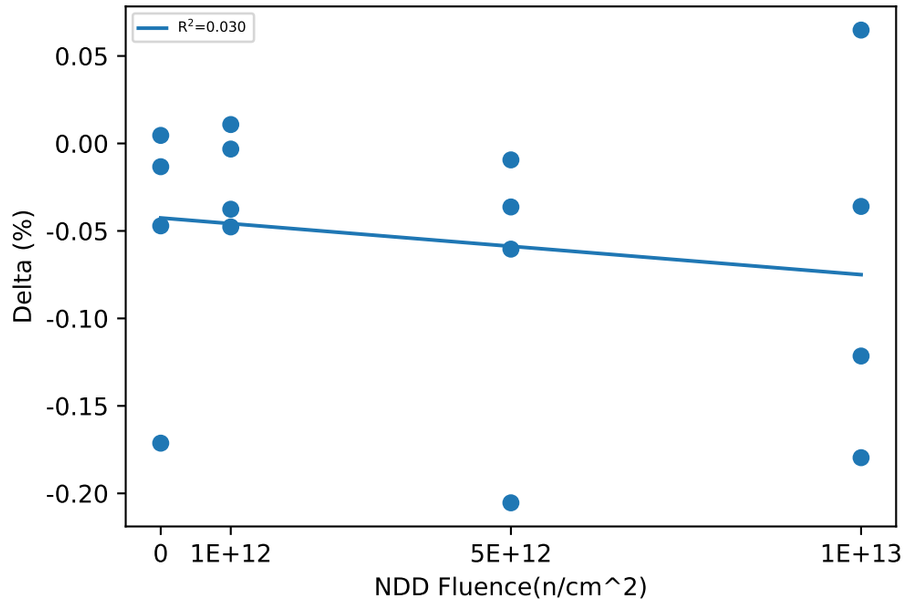
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.693	45.759	45.839	0.070316	45.652	45.694	45.782	0.061184	-0.186	-0.064175	-0.0029	0.084218
1e+12	45.684	45.717	45.761	0.033223	45.604	45.69	45.761	0.066498	-0.0808	-0.027575	0.0008	0.036553
5e+12	45.666	45.75	45.842	0.091984	45.605	45.665	45.759	0.066093	-0.1941	-0.08555	-0.0189	0.075692
1e+13	45.582	45.734	45.885	0.12697	45.53	45.661	45.823	0.14285	-0.1687	-0.072825	0.0541	0.10412

Device Test: 27.46 LEVEL|WRST_MAX/OUT/5/5/0/0/5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

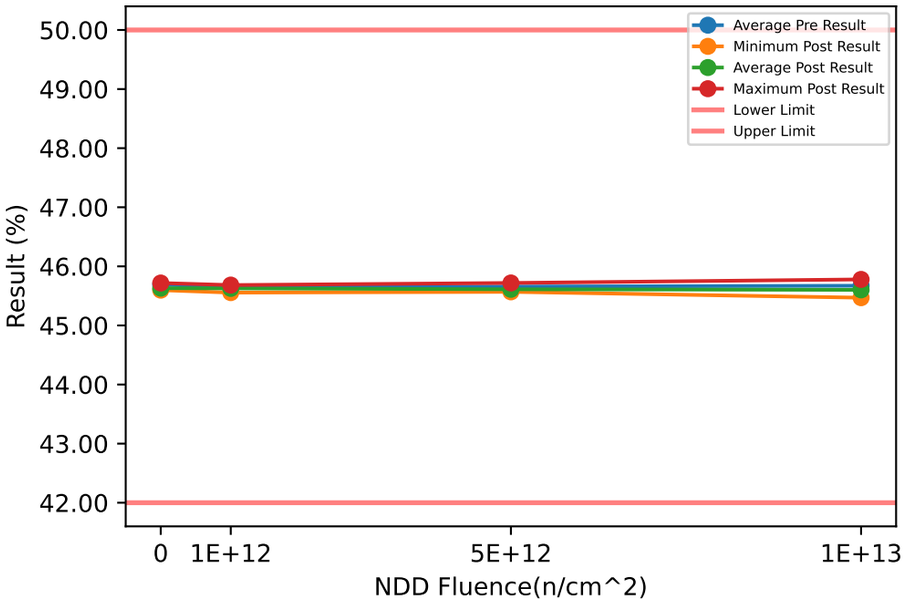
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.773	45.602	-0.1713
466	1e+12	NDD	45.669	45.666	-0.0032
762	0	CORRELATION	45.651	45.604	-0.0471
769	1e+12	NDD	45.679	45.69	0.0108
887	1e+12	NDD	45.603	45.565	-0.0376
891	0	CORRELATION	45.632	45.619	-0.0133
927	1e+12	NDD	45.66	45.612	-0.0477
967	5e+12	NDD	45.732	45.723	-0.0094
1204	1e+13	NDD	45.518	45.482	-0.036
1284	1e+13	NDD	45.658	45.478	-0.1796
1292	5e+12	NDD	45.617	45.581	-0.0363
1364	1e+13	NDD	45.84	45.718	-0.1215
1383	5e+12	NDD	45.604	45.543	-0.0604
1388	5e+12	NDD	45.778	45.573	-0.2054
1427	1e+13	NDD	45.698	45.763	0.0648
1666	0	CORRELATION	45.741	45.745	0.0046

Test Statistics (%)

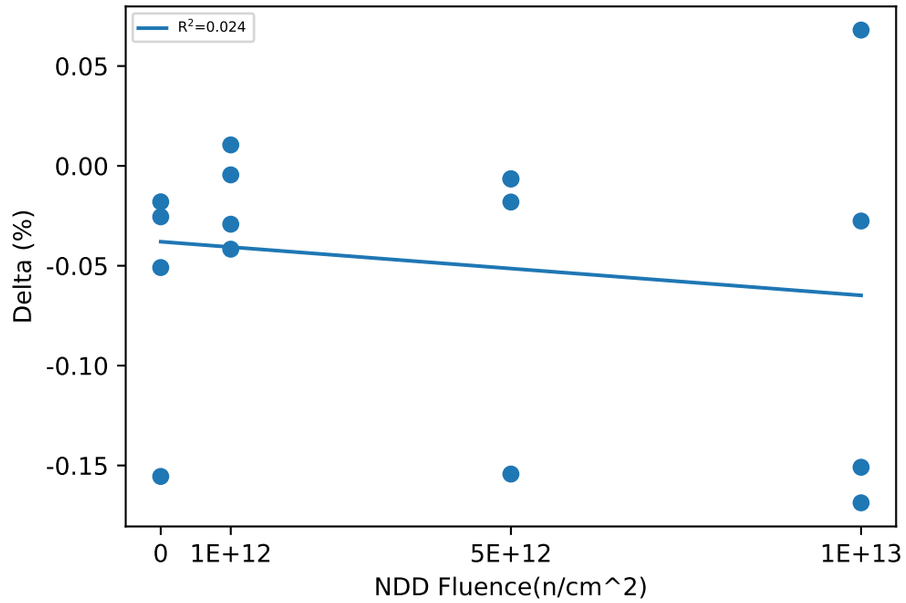
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.632	45.699	45.773	0.06825	45.602	45.642	45.745	0.069156	-0.1713	-0.056775	0.0046	0.079302
1e+12	45.603	45.653	45.679	0.034101	45.565	45.633	45.69	0.055704	-0.0477	-0.019425	0.0108	0.027728
5e+12	45.604	45.683	45.778	0.085829	45.543	45.605	45.723	0.080141	-0.2054	-0.077875	-0.0094	0.087532
1e+13	45.518	45.678	45.84	0.1323	45.478	45.61	45.763	0.15138	-0.1796	-0.068075	0.0648	0.10642

Device Test: 27.47 LEVEL|WRST_MAX/OUT/12/12/0/0/5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

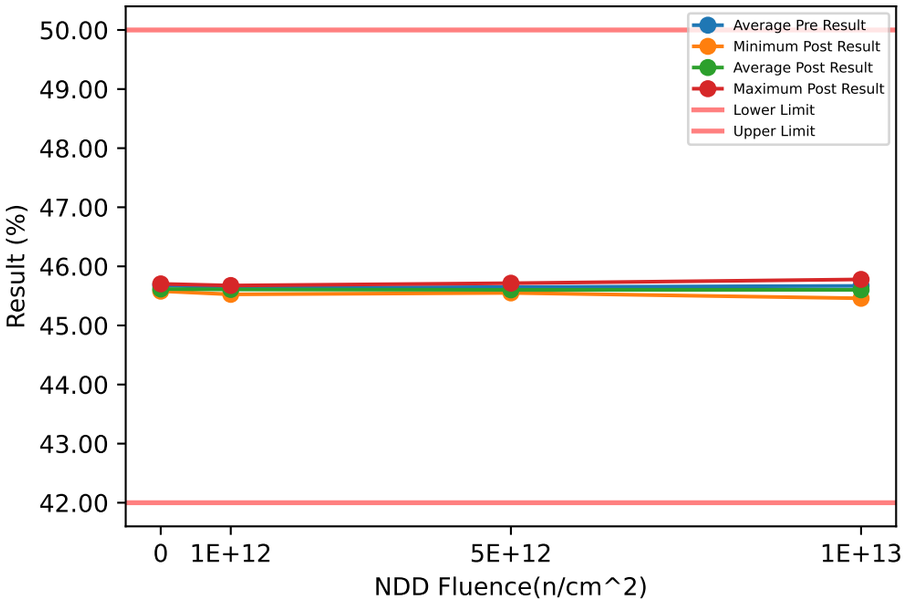
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.754	45.599	-0.1555
466	1e+12	NDD	45.664	45.635	-0.0292
762	0	CORRELATION	45.659	45.608	-0.0509
769	1e+12	NDD	45.688	45.683	-0.0045
887	1e+12	NDD	45.597	45.555	-0.0417
891	0	CORRELATION	45.623	45.597	-0.0255
927	1e+12	NDD	45.624	45.635	0.0105
967	5e+12	NDD	45.725	45.719	-0.0065
1204	1e+13	NDD	45.497	45.469	-0.0276
1284	1e+13	NDD	45.645	45.477	-0.1687
1292	5e+12	NDD	45.579	45.573	-0.0065
1364	1e+13	NDD	45.834	45.683	-0.1509
1383	5e+12	NDD	45.587	45.569	-0.0181
1388	5e+12	NDD	45.741	45.587	-0.1543
1427	1e+13	NDD	45.711	45.779	0.068
1666	0	CORRELATION	45.736	45.718	-0.018

Test Statistics (%)

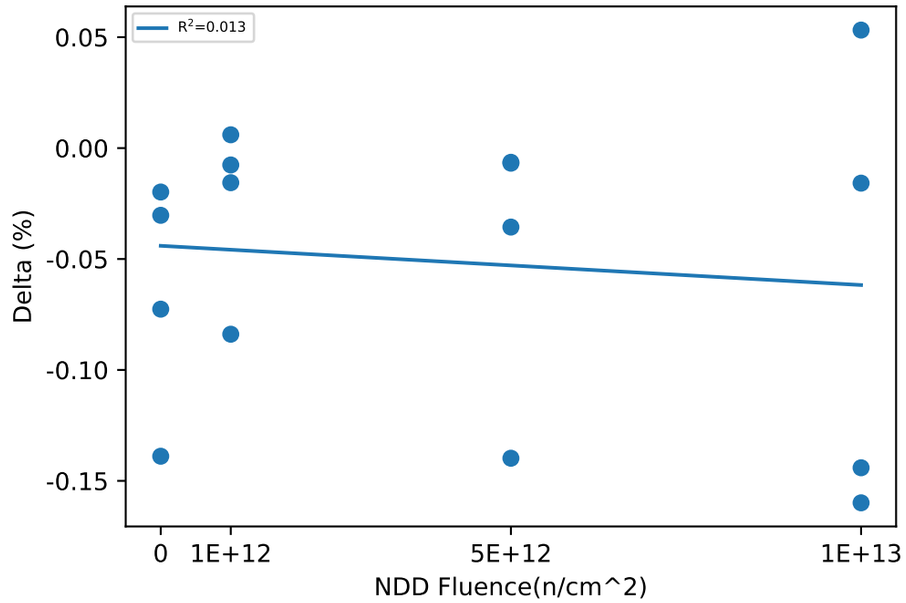
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.623	45.693	45.754	0.062345	45.597	45.63	45.718	0.058428	-0.1555	-0.062475	-0.018	0.063595
1e+12	45.597	45.643	45.688	0.040423	45.555	45.627	45.683	0.052891	-0.0417	-0.016225	0.0105	0.023587
5e+12	45.579	45.658	45.741	0.086978	45.569	45.612	45.719	0.071801	-0.1543	-0.04635	-0.0065	0.072174
1e+13	45.497	45.672	45.834	0.14022	45.469	45.602	45.779	0.1539	-0.1687	-0.0698	0.068	0.11125

Device Test: 27.48 LEVEL|WRST_MAX/OUT/14/14/0/0/5/1MHz//@MAX_DCL_50

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 42.0, Upper Limit = 50.0 (%))

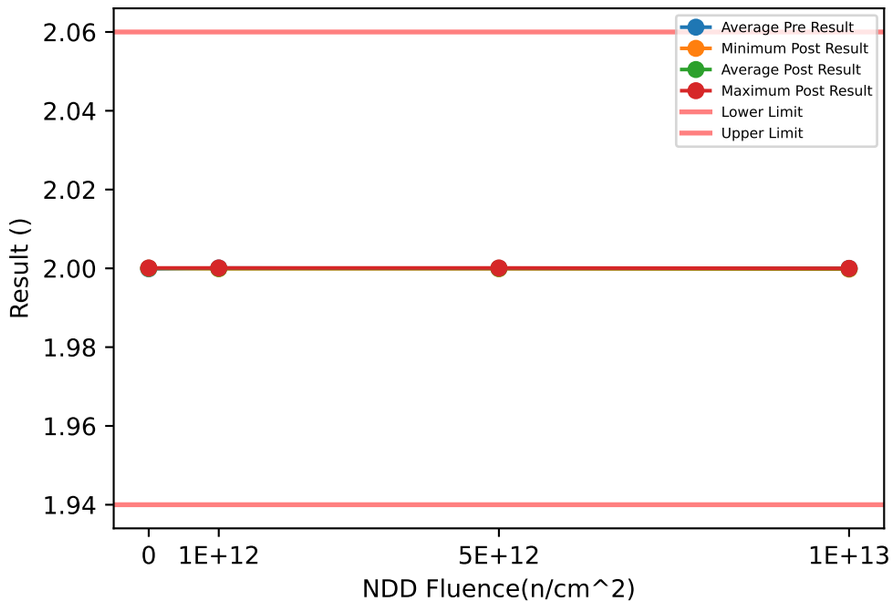
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	45.74	45.601	-0.1389
466	1e+12	NDD	45.638	45.622	-0.0156
762	0	CORRELATION	45.653	45.58	-0.0726
769	1e+12	NDD	45.683	45.676	-0.0076
887	1e+12	NDD	45.61	45.526	-0.0839
891	0	CORRELATION	45.6	45.58	-0.0198
927	1e+12	NDD	45.604	45.61	0.006
967	5e+12	NDD	45.722	45.715	-0.0068
1204	1e+13	NDD	45.475	45.459	-0.0158
1284	1e+13	NDD	45.627	45.483	-0.1441
1292	5e+12	NDD	45.557	45.55	-0.0064
1364	1e+13	NDD	45.849	45.689	-0.1599
1383	5e+12	NDD	45.588	45.552	-0.0356
1388	5e+12	NDD	45.731	45.592	-0.1398
1427	1e+13	NDD	45.725	45.779	0.0532
1666	0	CORRELATION	45.734	45.703	-0.0303

Test Statistics (%)

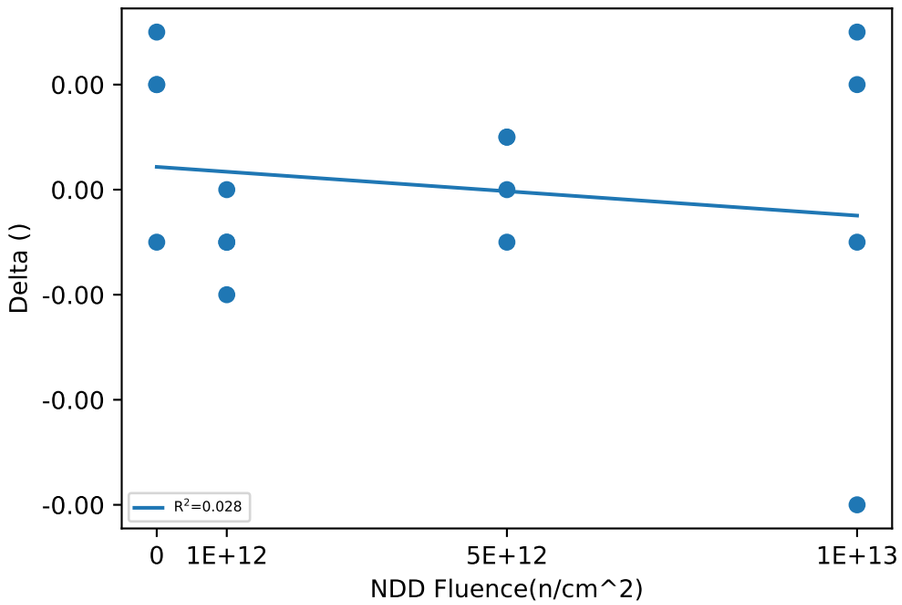
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	45.6	45.682	45.74	0.067328	45.58	45.616	45.703	0.058859	-0.1389	-0.0654	-0.0198	0.054054
1e+12	45.604	45.634	45.683	0.036194	45.526	45.609	45.676	0.062043	-0.0839	-0.025275	0.006	0.040088
5e+12	45.557	45.649	45.731	0.09008	45.55	45.602	45.715	0.077449	-0.1398	-0.04715	-0.0064	0.063262
1e+13	45.475	45.669	45.849	0.15821	45.459	45.602	45.779	0.15653	-0.1599	-0.06665	0.0532	0.1027

Device Test: 28.1 LEVEL|RATIO/CS/4.5/4.5/0/0/4.5/500kHz//@C_CS_R

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

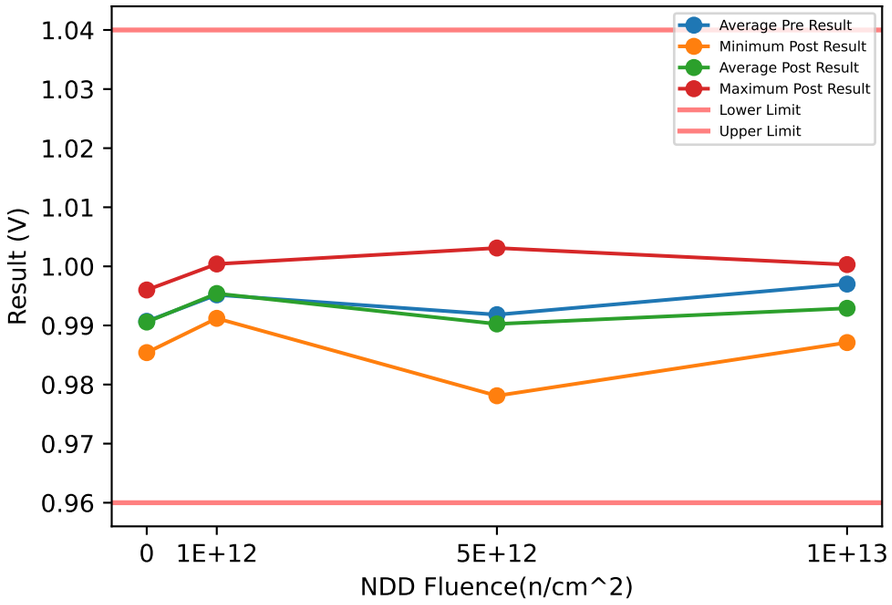
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	1.9998	2	0.0002
466	1e+12	NDD	2	1.9999	-0.0001
762	0	CORRELATION	2.0001	2	-0.0001
769	1e+12	NDD	2.0001	1.9999	-0.0002
887	1e+12	NDD	2.0001	2	-0.0001
891	0	CORRELATION	1.9998	2	0.0002
927	1e+12	NDD	2.0001	2.0001	0
967	5e+12	NDD	2	1.9999	-0.0001
1204	1e+13	NDD	2.0004	1.9998	-0.0006
1284	1e+13	NDD	1.9998	2	0.0002
1292	5e+12	NDD	2	2	0
1364	1e+13	NDD	1.9997	2	0.0003
1383	5e+12	NDD	1.9999	2	0.0001
1388	5e+12	NDD	2	2.0001	0.0001
1427	1e+13	NDD	2	1.9999	-0.0001
1666	0	CORRELATION	1.9998	2.0001	0.0003

Test Statistics ()

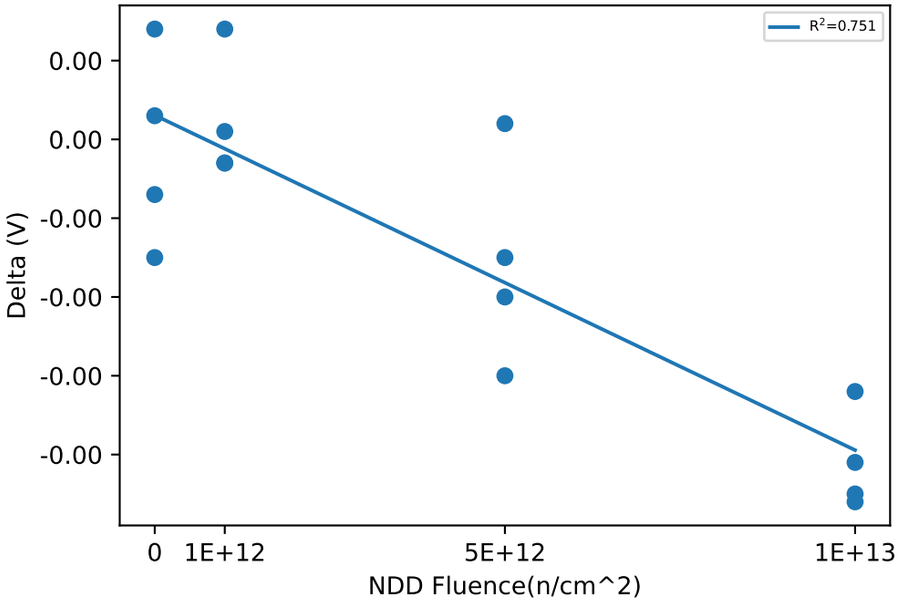
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9998	1.9999	2.0001	0.00015	2	2	2.0001	5e-05	-0.0001	0.00015	0.0003	0.00017321
1e+12	2	2.0001	2.0001	5e-05	1.9999	2	2.0001	9.5743e-05	-0.0002	-0.0001	0	8.165e-05
5e+12	1.9999	2	2	5e-05	1.9999	2	2.0001	8.165e-05	-0.0001	2.5e-05	0.0001	9.5743e-05
1e+13	1.9997	2	2.0004	0.00030957	1.9998	1.9999	2	9.5743e-05	-0.0006	-5e-05	0.0003	0.00040415

Device Test: 28.10 VOLTAGE|OC/CS/5/5/0/0/5/100kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

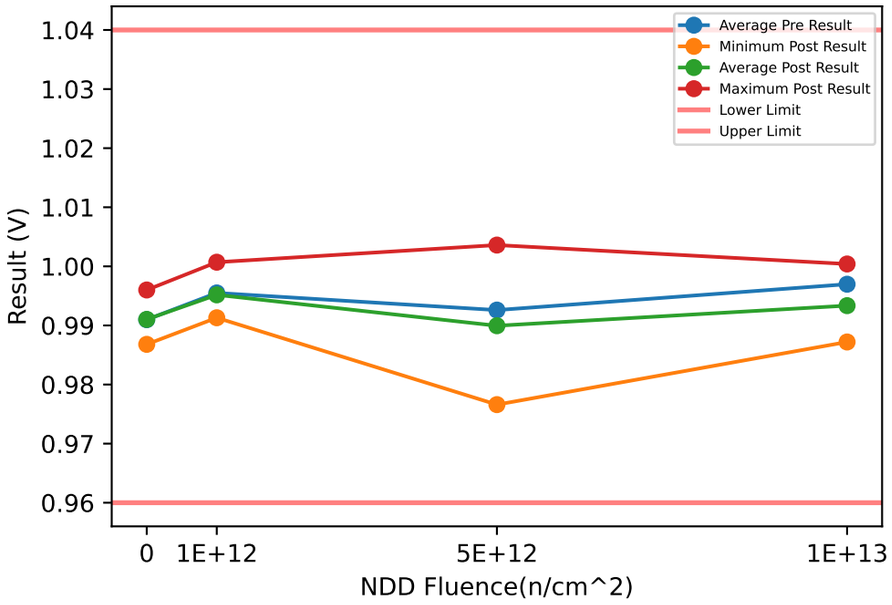
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9869	0.9883	0.0014
466	1e+12	NDD	0.9959	0.9956	-0.0003
762	0	CORRELATION	0.9957	0.996	0.0003
769	1e+12	NDD	0.993	0.9944	0.0014
887	1e+12	NDD	0.9915	0.9912	-0.0003
891	0	CORRELATION	0.9869	0.9854	-0.0015
927	1e+12	NDD	1.0003	1.0004	0.0001
967	5e+12	NDD	1.0051	1.0031	-0.002
1204	1e+13	NDD	0.9944	0.9898	-0.0046
1284	1e+13	NDD	1.0035	1.0003	-0.0032
1292	5e+12	NDD	0.9929	0.9914	-0.0015
1364	1e+13	NDD	0.9989	0.9944	-0.0045
1383	5e+12	NDD	0.9779	0.9781	0.0002
1388	5e+12	NDD	0.9914	0.9884	-0.003
1427	1e+13	NDD	0.9912	0.9871	-0.0041
1666	0	CORRELATION	0.9933	0.9926	-0.0007

Test Statistics (V)

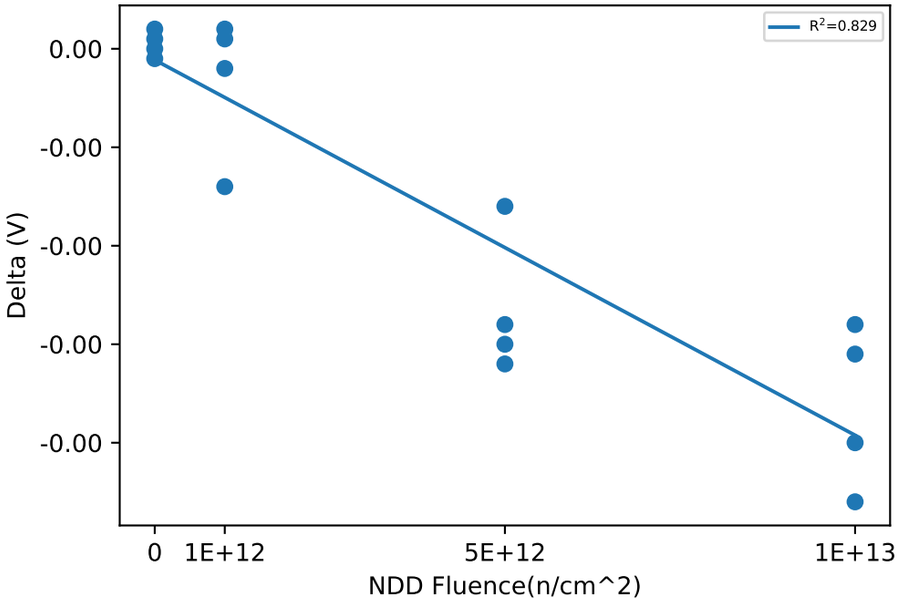
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9869	0.9907	0.9957	0.0044959	0.9854	0.99057	0.996	0.0046722	-0.0015	-0.000125	0.0014	0.0012553
1e+12	0.9915	0.99518	1.0003	0.0038742	0.9912	0.9954	1.0004	0.0038158	-0.0003	0.000225	0.0014	0.00080571
5e+12	0.9779	0.99182	1.0051	0.011128	0.9781	0.99025	1.0031	0.010287	-0.003	-0.001575	0.0002	0.0013376
1e+13	0.9912	0.997	1.0035	0.0053622	0.9871	0.9929	1.0003	0.005781	-0.0046	-0.0041	-0.0032	0.0006377

Device Test: 28.11 VOLTAGE|OC/CS/12/12/0/0/5/100kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

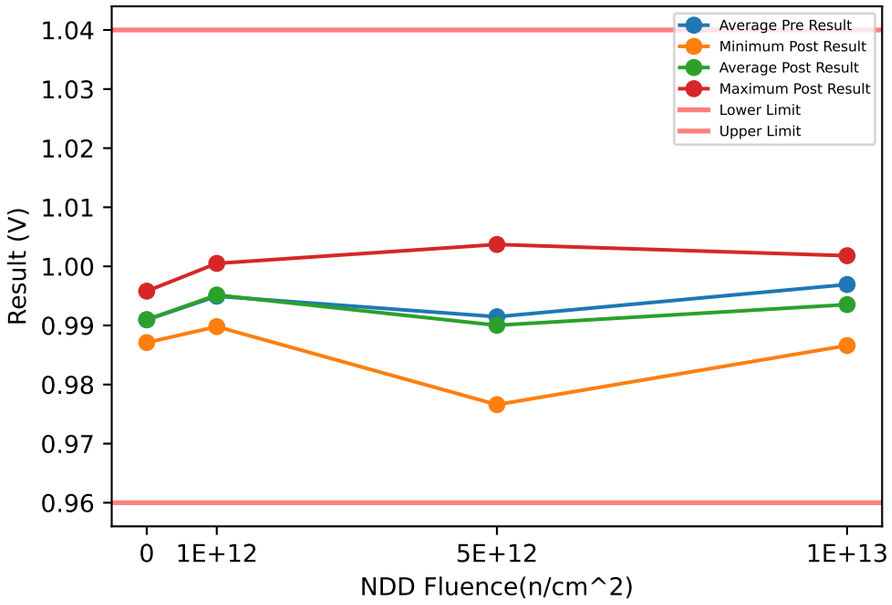
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9882	0.9884	0.0002
466	1e+12	NDD	0.9959	0.9957	-0.0002
762	0	CORRELATION	0.9959	0.996	0.0001
769	1e+12	NDD	0.9944	0.993	-0.0014
887	1e+12	NDD	0.9912	0.9913	0.0001
891	0	CORRELATION	0.9869	0.9868	-0.0001
927	1e+12	NDD	1.0005	1.0007	0.0002
967	5e+12	NDD	1.0064	1.0036	-0.0028
1204	1e+13	NDD	0.9944	0.9898	-0.0046
1284	1e+13	NDD	1.0035	1.0004	-0.0031
1292	5e+12	NDD	0.9929	0.9913	-0.0016
1364	1e+13	NDD	0.9988	0.996	-0.0028
1383	5e+12	NDD	0.9796	0.9766	-0.003
1388	5e+12	NDD	0.9915	0.9883	-0.0032
1427	1e+13	NDD	0.9912	0.9872	-0.004
1666	0	CORRELATION	0.9929	0.9929	0

Test Statistics (V)

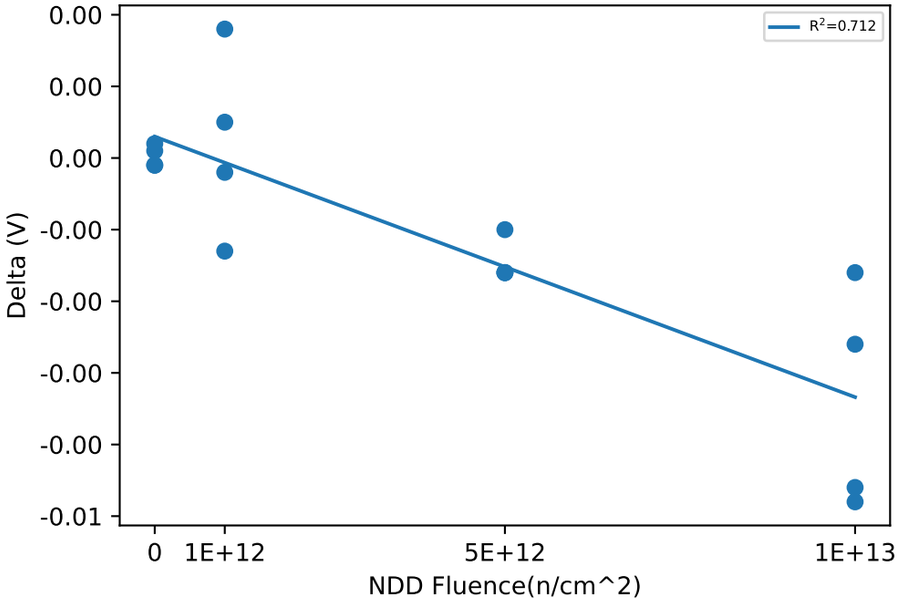
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9869	0.99097	0.9959	0.004174	0.9868	0.99103	0.996	0.0042035	-0.0001	5e-05	0.0002	0.0001291
1e+12	0.9912	0.9955	1.0005	0.003867	0.9913	0.99517	1.0007	0.0041048	-0.0014	-0.000325	0.0002	0.00073655
5e+12	0.9796	0.9926	1.0064	0.010966	0.9766	0.98995	1.0036	0.011092	-0.0032	-0.00265	-0.0016	0.0007188
1e+13	0.9912	0.99697	1.0035	0.0053506	0.9872	0.99335	1.0004	0.0059763	-0.0046	-0.003625	-0.0028	0.00082614

Device Test: 28.12 VOLTAGE|OC/CS/14/14/0/0/5/100kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

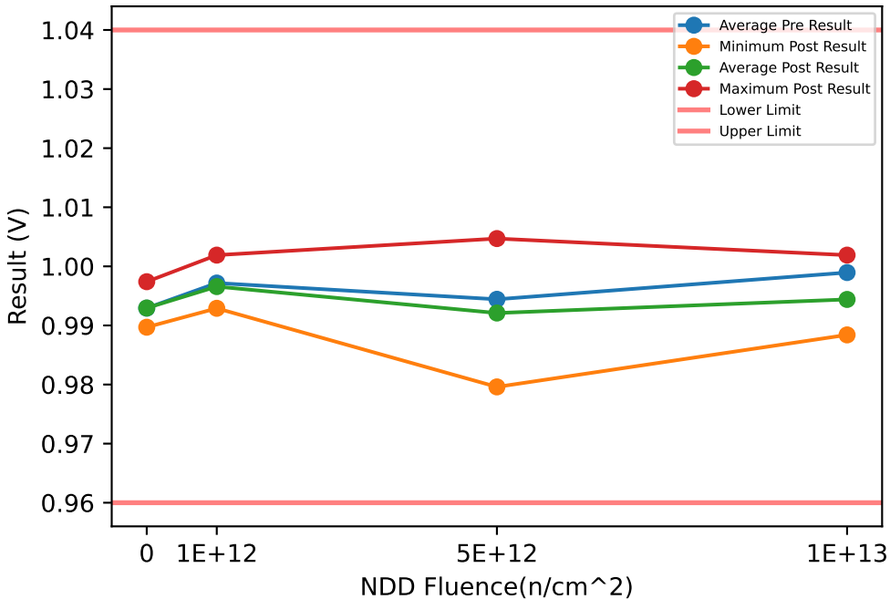
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9884	0.9883	-0.0001
466	1e+12	NDD	0.9959	0.9957	-0.0002
762	0	CORRELATION	0.9959	0.9958	-0.0001
769	1e+12	NDD	0.9941	0.9946	0.0005
887	1e+12	NDD	0.9911	0.9898	-0.0013
891	0	CORRELATION	0.9869	0.9871	0.0002
927	1e+12	NDD	0.9987	1.0005	0.0018
967	5e+12	NDD	1.0047	1.0037	-0.001
1204	1e+13	NDD	0.9945	0.9897	-0.0048
1284	1e+13	NDD	1.0034	1.0018	-0.0016
1292	5e+12	NDD	0.993	0.9914	-0.0016
1364	1e+13	NDD	0.9986	0.996	-0.0026
1383	5e+12	NDD	0.9782	0.9766	-0.0016
1388	5e+12	NDD	0.99	0.9884	-0.0016
1427	1e+13	NDD	0.9912	0.9866	-0.0046
1666	0	CORRELATION	0.9926	0.9927	0.0001

Test Statistics (V)

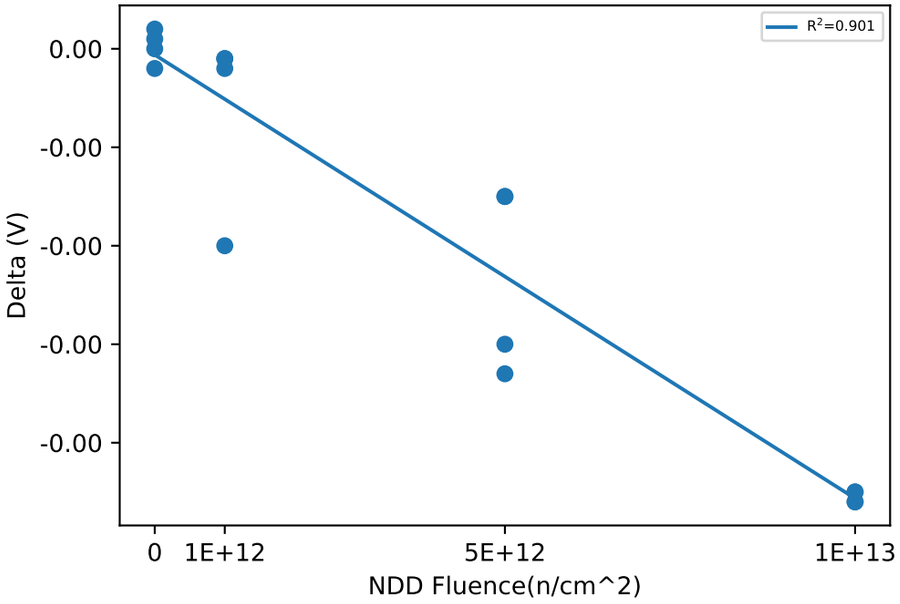
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9869	0.99095	0.9959	0.0040878	0.9871	0.99097	0.9958	0.0040178	-0.0001	2.5e-05	0.0002	0.00015
1e+12	0.9911	0.99495	0.9987	0.003189	0.9898	0.99515	1.0005	0.0043913	-0.0013	0.0002	0.0018	0.0012987
5e+12	0.9782	0.99147	1.0047	0.010888	0.9766	0.99002	1.0037	0.011132	-0.0016	-0.00145	-0.001	0.0003
1e+13	0.9912	0.99693	1.0034	0.0052722	0.9866	0.99352	1.0018	0.0067623	-0.0048	-0.0034	-0.0016	0.0015578

Device Test: 28.13 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/500kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

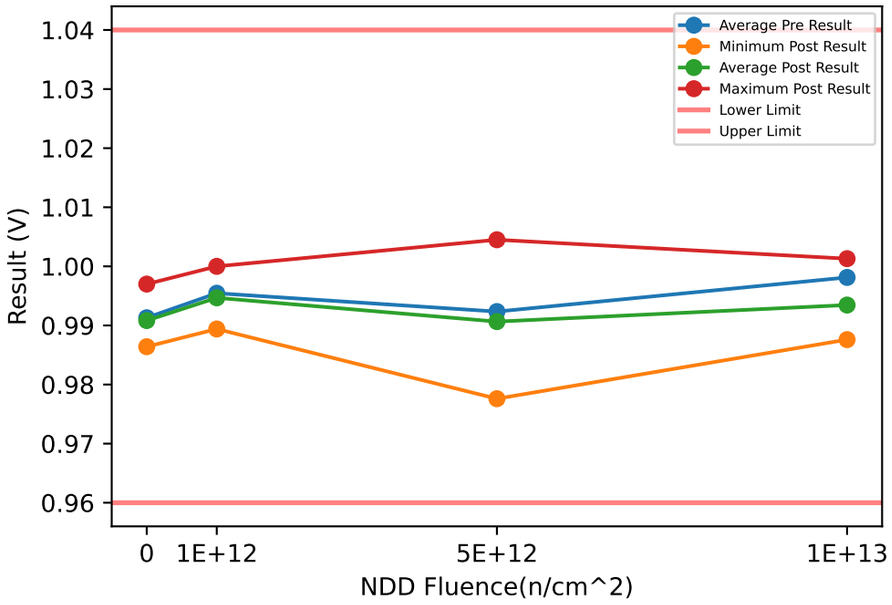
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9899	0.99	0.0001
466	1e+12	NDD	0.9975	0.9974	-0.0001
762	0	CORRELATION	0.9974	0.9974	0
769	1e+12	NDD	0.9961	0.9941	-0.002
887	1e+12	NDD	0.9931	0.9929	-0.0002
891	0	CORRELATION	0.9899	0.9897	-0.0002
927	1e+12	NDD	1.002	1.0019	-0.0001
967	5e+12	NDD	1.0077	1.0047	-0.003
1204	1e+13	NDD	0.9959	0.9914	-0.0045
1284	1e+13	NDD	1.0065	1.0019	-0.0046
1292	5e+12	NDD	0.996	0.9927	-0.0033
1364	1e+13	NDD	1.0004	0.9959	-0.0045
1383	5e+12	NDD	0.9811	0.9796	-0.0015
1388	5e+12	NDD	0.9929	0.9914	-0.0015
1427	1e+13	NDD	0.993	0.9884	-0.0046
1666	0	CORRELATION	0.9945	0.9947	0.0002

Test Statistics (V)

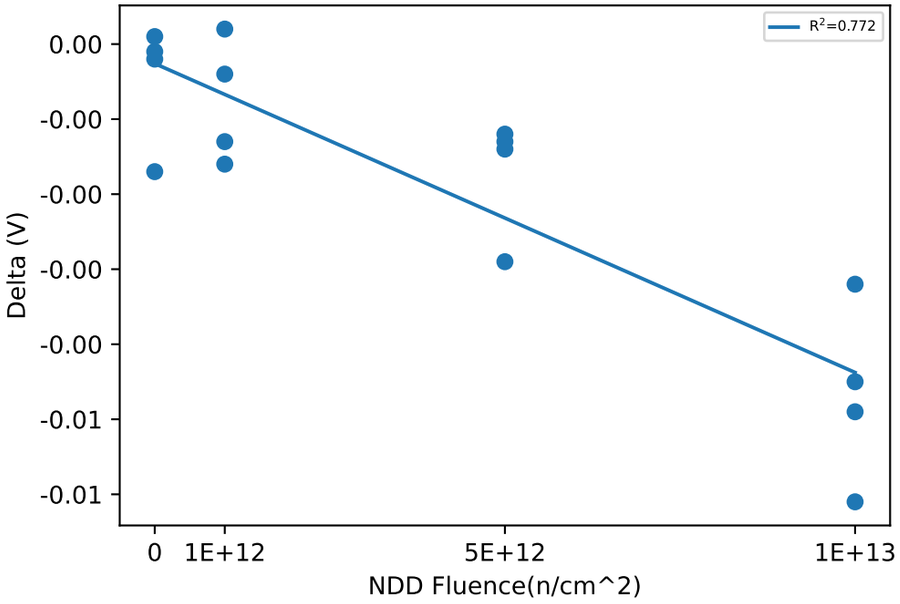
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9899	0.99293	0.9974	0.0036882	0.9897	0.99295	0.9974	0.0037474	-0.0002	2.5e-05	0.0002	0.00017078
1e+12	0.9931	0.99718	1.002	0.0037035	0.9929	0.99657	1.0019	0.0040277	-0.002	-0.0006	-0.0001	0.00093452
5e+12	0.9811	0.99443	1.0077	0.010933	0.9796	0.9921	1.0047	0.010261	-0.0033	-0.002325	-0.0015	0.00096047
1e+13	0.993	0.99895	1.0065	0.0058825	0.9884	0.9944	1.0019	0.0058737	-0.0046	-0.00455	-0.0045	5.7735e-05

Device Test: 28.14 VOLTAGE|OC/CS/5/5/0/0/5/500kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

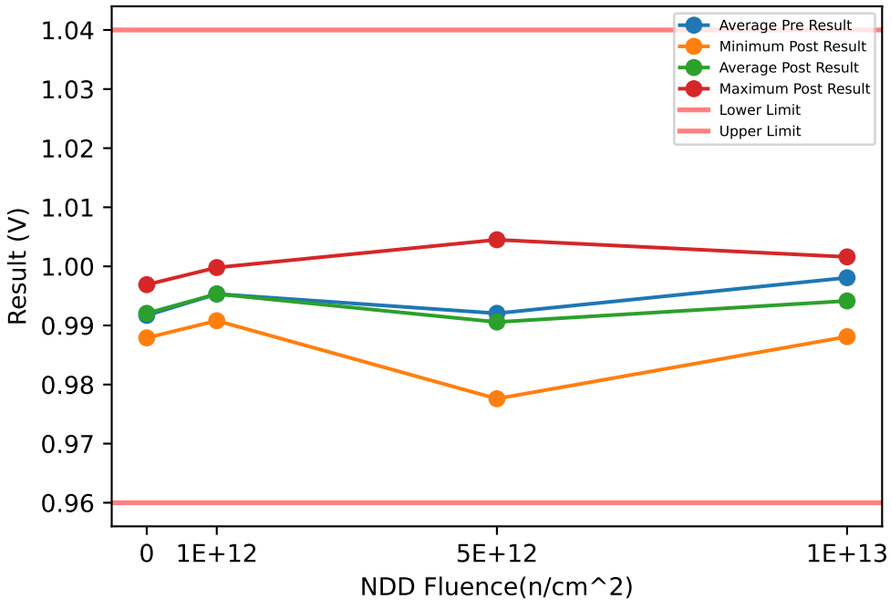
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9881	0.9879	-0.0002
466	1e+12	NDD	0.9969	0.9956	-0.0013
762	0	CORRELATION	0.9969	0.997	0.0001
769	1e+12	NDD	0.9941	0.9937	-0.0004
887	1e+12	NDD	0.991	0.9894	-0.0016
891	0	CORRELATION	0.9881	0.9864	-0.0017
927	1e+12	NDD	0.9998	1	0.0002
967	5e+12	NDD	1.0057	1.0045	-0.0012
1204	1e+13	NDD	0.9955	0.9894	-0.0061
1284	1e+13	NDD	1.0045	1.0013	-0.0032
1292	5e+12	NDD	0.994	0.9911	-0.0029
1364	1e+13	NDD	1	0.9955	-0.0045
1383	5e+12	NDD	0.979	0.9776	-0.0014
1388	5e+12	NDD	0.9907	0.9894	-0.0013
1427	1e+13	NDD	0.9925	0.9876	-0.0049
1666	0	CORRELATION	0.9921	0.992	-0.0001

Test Statistics (V)

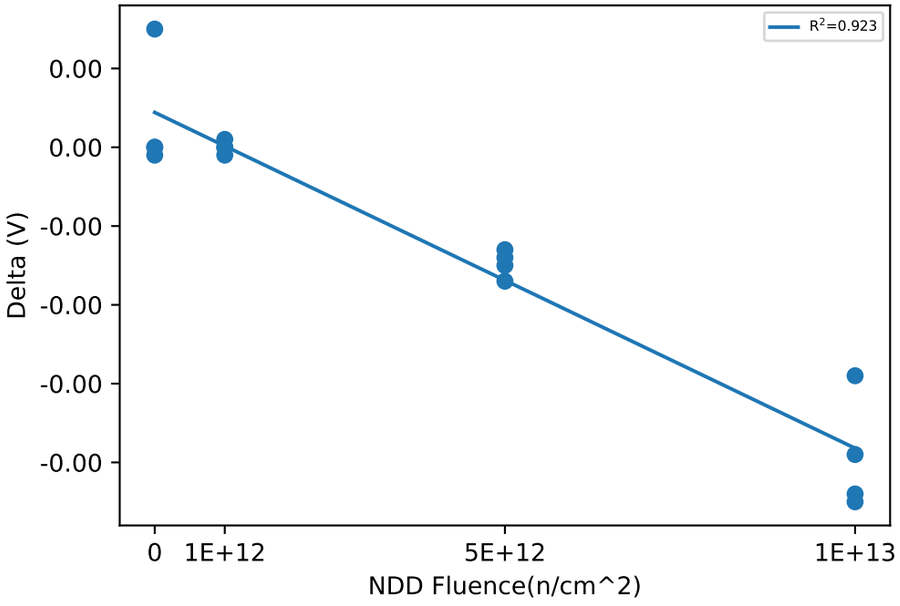
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9881	0.9913	0.9969	0.0041825	0.9864	0.99083	0.997	0.0047486	-0.0017	-0.000475	0.0001	0.00082614
1e+12	0.991	0.99545	0.9998	0.0037705	0.9894	0.99467	1	0.0043965	-0.0016	-0.000775	0.0002	0.00082614
5e+12	0.979	0.99235	1.0057	0.010983	0.9776	0.99065	1.0045	0.011013	-0.0029	-0.0017	-0.0012	0.00080416
1e+13	0.9925	0.99813	1.0045	0.00525	0.9876	0.99345	1.0013	0.0062303	-0.0061	-0.004675	-0.0032	0.0011955

Device Test: 28.15 VOLTAGE|OC/CS/12/12/0/0/5/500kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

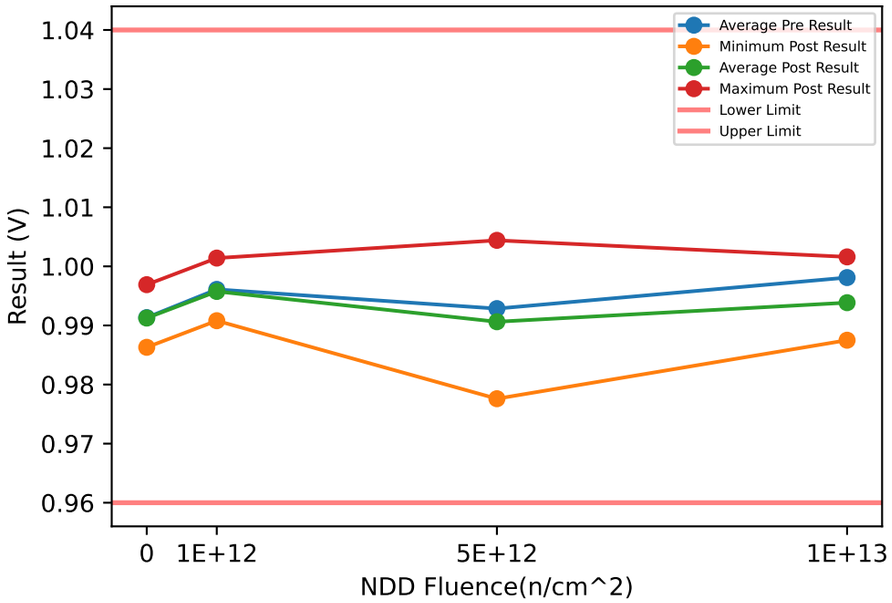
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9895	0.9895	0
466	1e+12	NDD	0.997	0.9971	0.0001
762	0	CORRELATION	0.9969	0.9969	0
769	1e+12	NDD	0.9936	0.9936	0
887	1e+12	NDD	0.9909	0.9908	-0.0001
891	0	CORRELATION	0.988	0.9879	-0.0001
927	1e+12	NDD	0.9998	0.9998	0
967	5e+12	NDD	1.0059	1.0045	-0.0014
1204	1e+13	NDD	0.9956	0.9912	-0.0044
1284	1e+13	NDD	1.0045	1.0016	-0.0029
1292	5e+12	NDD	0.9925	0.9908	-0.0017
1364	1e+13	NDD	0.9996	0.9957	-0.0039
1383	5e+12	NDD	0.9789	0.9776	-0.0013
1388	5e+12	NDD	0.9909	0.9894	-0.0015
1427	1e+13	NDD	0.9926	0.9881	-0.0045
1666	0	CORRELATION	0.9924	0.9939	0.0015

Test Statistics (V)

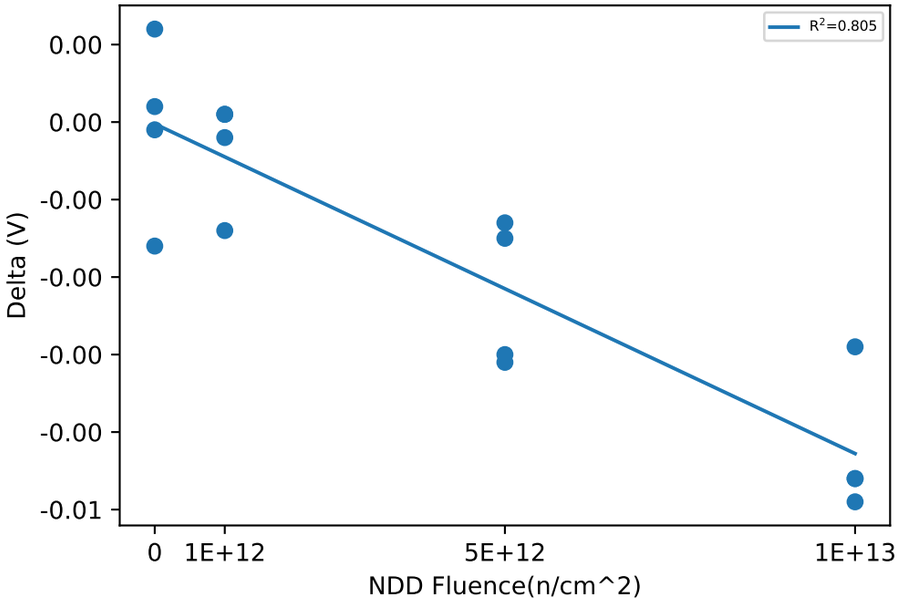
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.988	0.9917	0.9969	0.0039183	0.9879	0.99205	0.9969	0.0041097	-0.0001	0.00035	0.0015	0.00076811
1e+12	0.9909	0.99533	0.9998	0.0038896	0.9908	0.99533	0.9998	0.0039424	-0.0001	0	0.0001	8.165e-05
5e+12	0.9789	0.99205	1.0059	0.011049	0.9776	0.99057	1.0045	0.01101	-0.0017	-0.001475	-0.0013	0.00017078
1e+13	0.9926	0.99808	1.0045	0.0051545	0.9881	0.99415	1.0016	0.0058654	-0.0045	-0.003925	-0.0029	0.00073201

Device Test: 28.16 VOLTAGE|OC/CS/14/14/0/0/5/500kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

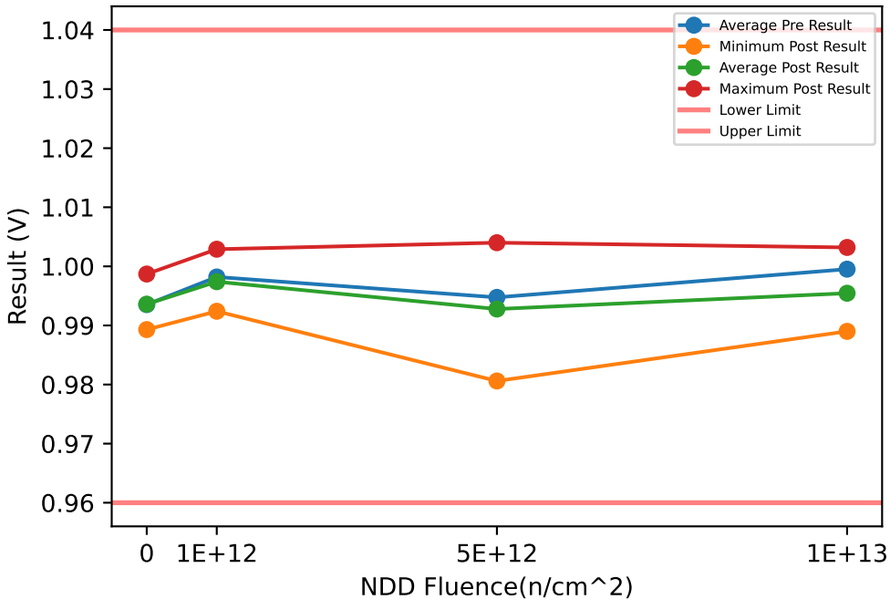
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9879	0.9881	0.0002
466	1e+12	NDD	0.997	0.9971	0.0001
762	0	CORRELATION	0.997	0.9969	-0.0001
769	1e+12	NDD	0.9936	0.9937	0.0001
887	1e+12	NDD	0.9922	0.9908	-0.0014
891	0	CORRELATION	0.9879	0.9863	-0.0016
927	1e+12	NDD	1.0016	1.0014	-0.0002
967	5e+12	NDD	1.0059	1.0044	-0.0015
1204	1e+13	NDD	0.9955	0.9909	-0.0046
1284	1e+13	NDD	1.0045	1.0016	-0.0029
1292	5e+12	NDD	0.9924	0.9911	-0.0013
1364	1e+13	NDD	1	0.9954	-0.0046
1383	5e+12	NDD	0.9806	0.9776	-0.003
1388	5e+12	NDD	0.9925	0.9894	-0.0031
1427	1e+13	NDD	0.9924	0.9875	-0.0049
1666	0	CORRELATION	0.9925	0.9937	0.0012

Test Statistics (V)

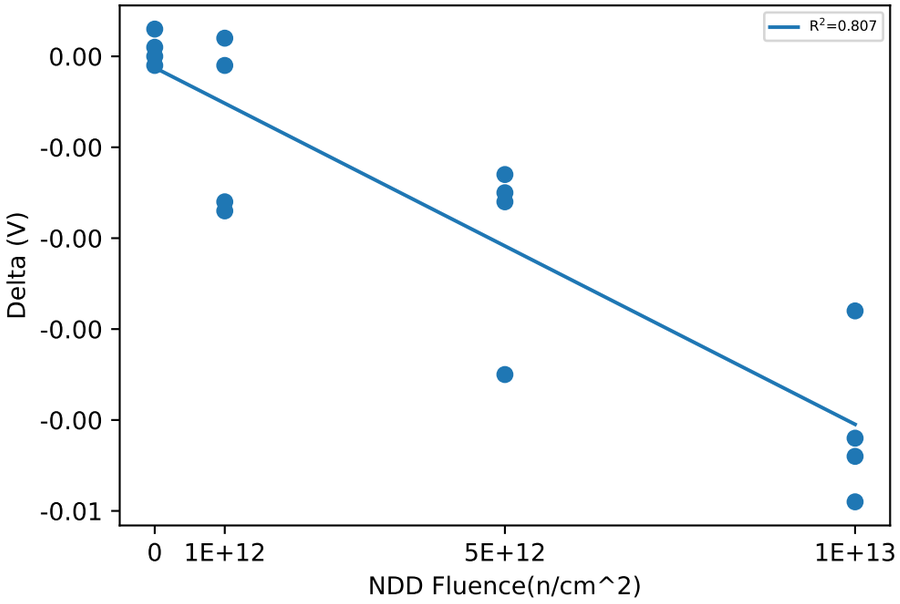
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9879	0.99133	0.997	0.0043607	0.9863	0.99125	0.9969	0.0049109	-0.0016	-7.5e-05	0.0012	0.0011587
1e+12	0.9922	0.9961	1.0016	0.0041841	0.9908	0.99575	1.0014	0.0045625	-0.0014	-0.00035	0.0001	0.00071414
5e+12	0.9806	0.99285	1.0059	0.010339	0.9776	0.99062	1.0044	0.010972	-0.0031	-0.002225	-0.0013	0.00095699
1e+13	0.9924	0.9981	1.0045	0.0052858	0.9875	0.99385	1.0016	0.0060962	-0.0049	-0.00425	-0.0029	0.00091104

Device Test: 28.17 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/1MHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

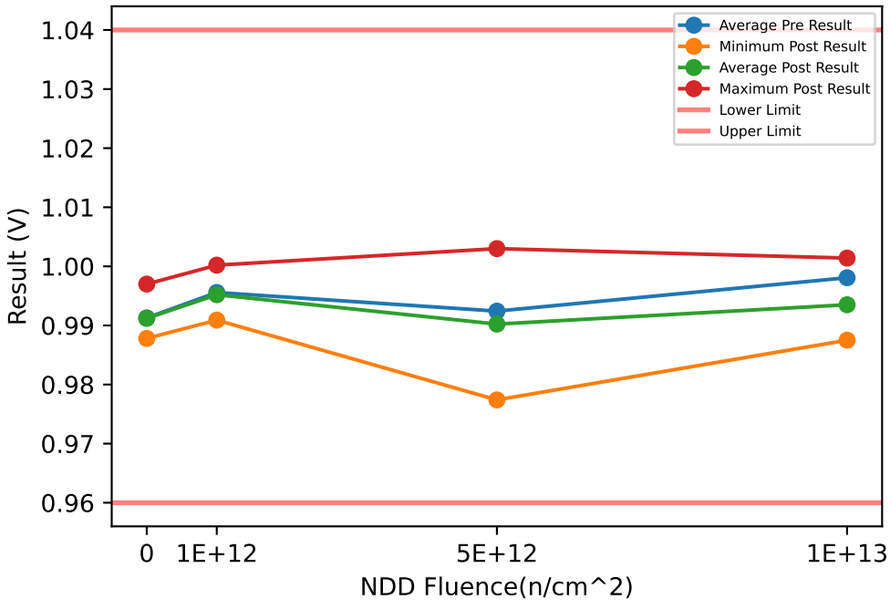
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.991	0.991	0
466	1e+12	NDD	0.9985	0.9987	0.0002
762	0	CORRELATION	0.9984	0.9987	0.0003
769	1e+12	NDD	0.9973	0.9956	-0.0017
887	1e+12	NDD	0.994	0.9924	-0.0016
891	0	CORRELATION	0.9894	0.9893	-0.0001
927	1e+12	NDD	1.003	1.0029	-0.0001
967	5e+12	NDD	1.0075	1.004	-0.0035
1204	1e+13	NDD	0.997	0.9926	-0.0044
1284	1e+13	NDD	1.006	1.0032	-0.0028
1292	5e+12	NDD	0.9954	0.9938	-0.0016
1364	1e+13	NDD	1.0012	0.997	-0.0042
1383	5e+12	NDD	0.9821	0.9806	-0.0015
1388	5e+12	NDD	0.994	0.9927	-0.0013
1427	1e+13	NDD	0.9939	0.989	-0.0049
1666	0	CORRELATION	0.9953	0.9954	0.0001

Test Statistics (V)

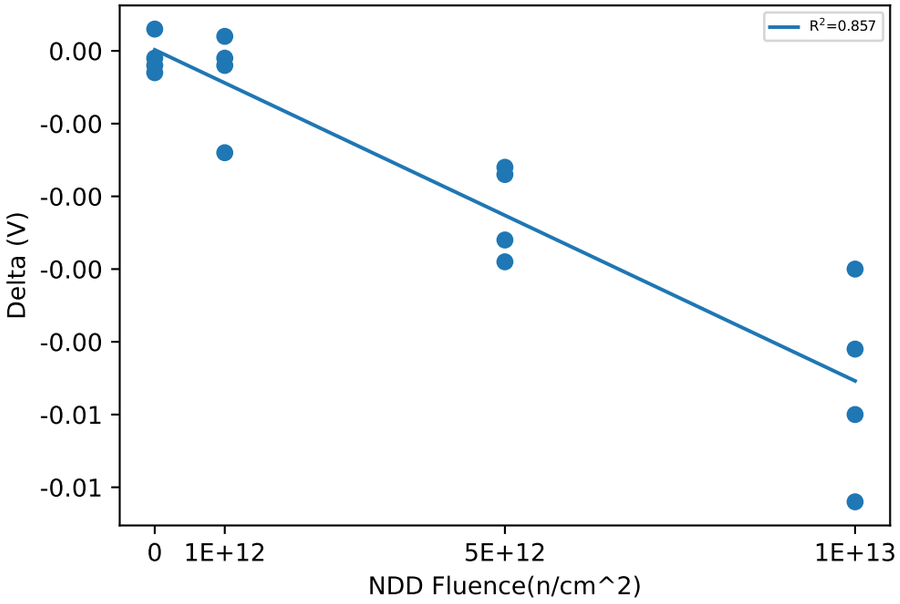
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9894	0.99352	0.9984	0.004095	0.9893	0.9936	0.9987	0.0042622	-0.0001	7.5e-05	0.0003	0.00017078
1e+12	0.994	0.9982	1.003	0.0037229	0.9924	0.9974	1.0029	0.0044788	-0.0017	-0.0008	0.0002	0.00098995
5e+12	0.9821	0.99475	1.0075	0.010385	0.9806	0.99277	1.004	0.0095793	-0.0035	-0.001975	-0.0013	0.0010243
1e+13	0.9939	0.99952	1.006	0.0052519	0.989	0.99545	1.0032	0.0061153	-0.0049	-0.004075	-0.0028	0.00089954

Device Test: 28.18 VOLTAGE|OC/CS/5/5/0/0/5/1MHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

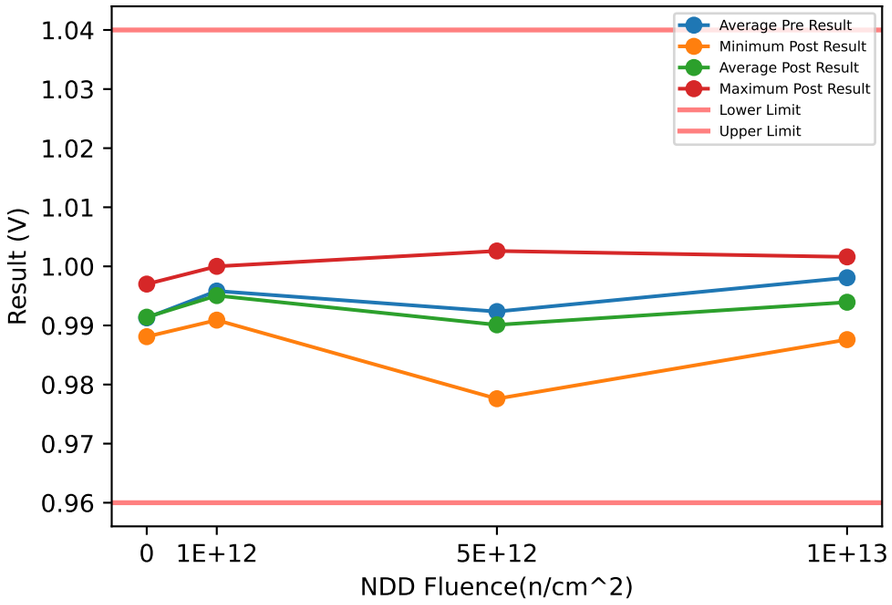
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.988	0.9878	-0.0002
466	1e+12	NDD	0.997	0.9956	-0.0014
762	0	CORRELATION	0.9967	0.997	0.0003
769	1e+12	NDD	0.9943	0.9941	-0.0002
887	1e+12	NDD	0.991	0.9909	-0.0001
891	0	CORRELATION	0.988	0.9879	-0.0001
927	1e+12	NDD	1	1.0002	0.0002
967	5e+12	NDD	1.0056	1.003	-0.0026
1204	1e+13	NDD	0.9956	0.9894	-0.0062
1284	1e+13	NDD	1.0044	1.0014	-0.003
1292	5e+12	NDD	0.994	0.9911	-0.0029
1364	1e+13	NDD	0.9998	0.9957	-0.0041
1383	5e+12	NDD	0.9791	0.9774	-0.0017
1388	5e+12	NDD	0.991	0.9894	-0.0016
1427	1e+13	NDD	0.9925	0.9875	-0.005
1666	0	CORRELATION	0.9924	0.9921	-0.0003

Test Statistics (V)

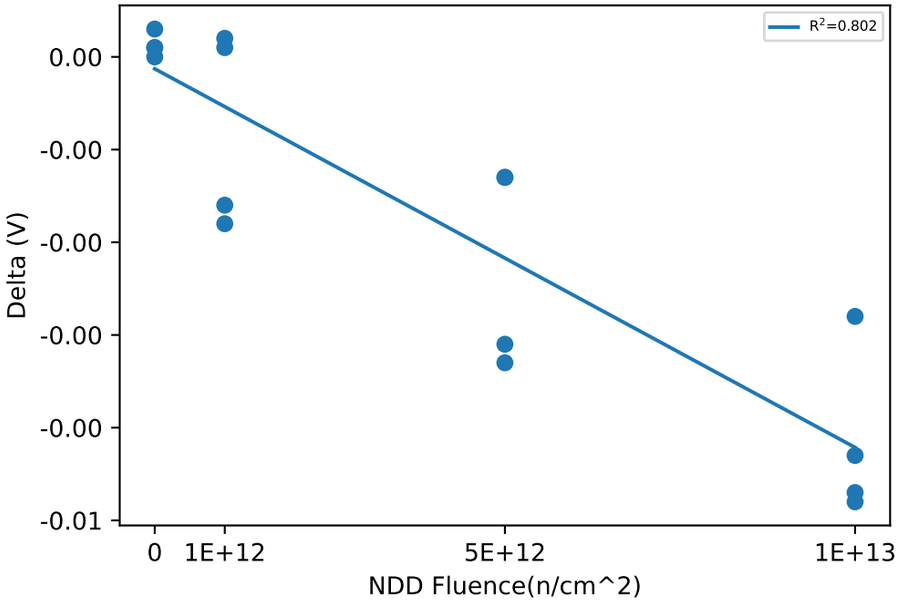
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.988	0.99128	0.9967	0.0041692	0.9878	0.9912	0.997	0.0043551	-0.0003	-7.5e-05	0.0003	0.000263
1e+12	0.991	0.99557	1	0.003837	0.9909	0.9952	1.0002	0.003867	-0.0014	-0.000375	0.0002	0.00070415
5e+12	0.9791	0.99243	1.0056	0.010888	0.9774	0.99022	1.003	0.010474	-0.0029	-0.0022	-0.0016	0.00064807
1e+13	0.9925	0.99808	1.0044	0.00517	0.9875	0.9935	1.0014	0.0063261	-0.0062	-0.004575	-0.003	0.0013574

Device Test: 28.19 VOLTAGE|OC/CS/12/12/0/0/5/1MHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

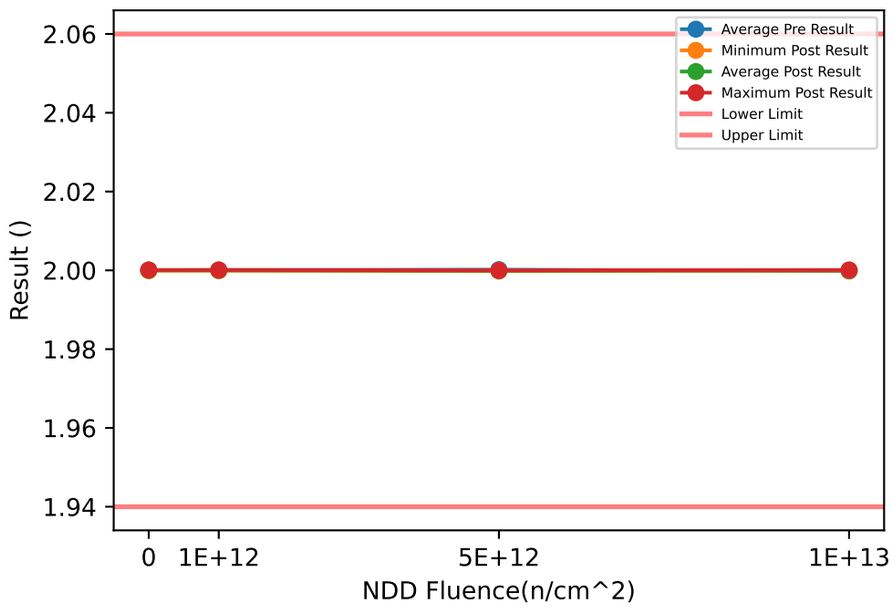
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9881	0.9881	0
466	1e+12	NDD	0.9969	0.9951	-0.0018
762	0	CORRELATION	0.9969	0.997	0.0001
769	1e+12	NDD	0.9941	0.9942	0.0001
887	1e+12	NDD	0.9925	0.9909	-0.0016
891	0	CORRELATION	0.988	0.9881	0.0001
927	1e+12	NDD	0.9998	1	0.0002
967	5e+12	NDD	1.0059	1.0026	-0.0033
1204	1e+13	NDD	0.9954	0.9911	-0.0043
1284	1e+13	NDD	1.0044	1.0016	-0.0028
1292	5e+12	NDD	0.9939	0.9908	-0.0031
1364	1e+13	NDD	1.0001	0.9954	-0.0047
1383	5e+12	NDD	0.9789	0.9776	-0.0013
1388	5e+12	NDD	0.9907	0.9894	-0.0013
1427	1e+13	NDD	0.9924	0.9876	-0.0048
1666	0	CORRELATION	0.9921	0.9924	0.0003

Test Statistics (V)

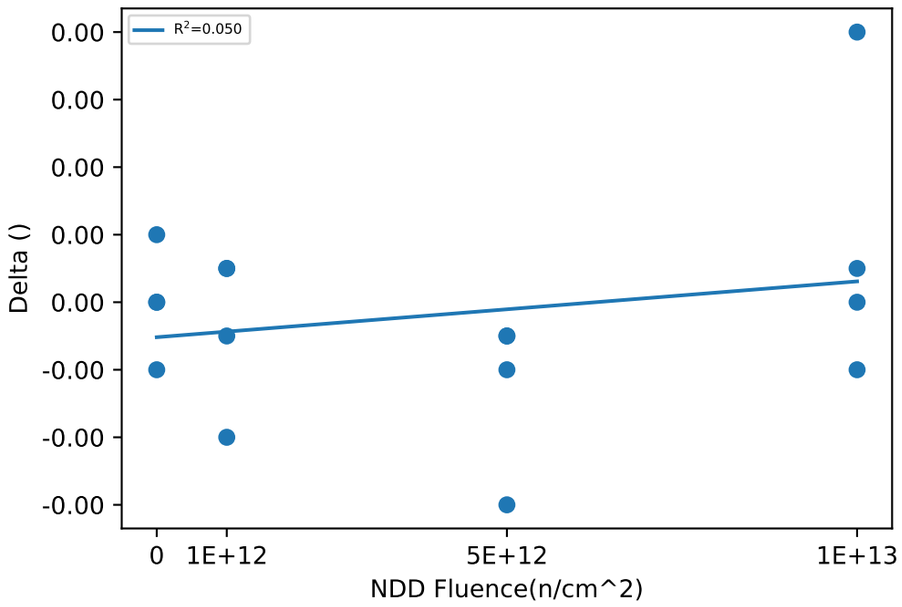
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.988	0.99128	0.9969	0.0042082	0.9881	0.9914	0.997	0.0042481	0	0.000125	0.0003	0.00012583
1e+12	0.9925	0.99582	0.9998	0.0032139	0.9909	0.99505	1	0.0037616	-0.0018	-0.000775	0.0002	0.001072
5e+12	0.9789	0.99235	1.0059	0.0111	0.9776	0.9901	1.0026	0.010222	-0.0033	-0.00225	-0.0013	0.0011
1e+13	0.9924	0.99808	1.0044	0.0052747	0.9876	0.99392	1.0016	0.0060296	-0.0048	-0.00415	-0.0028	0.00092556

Device Test: 28.2 LEVEL|RATIO/CS/5/5/0/0/5/500kHz//@C_CS_R

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

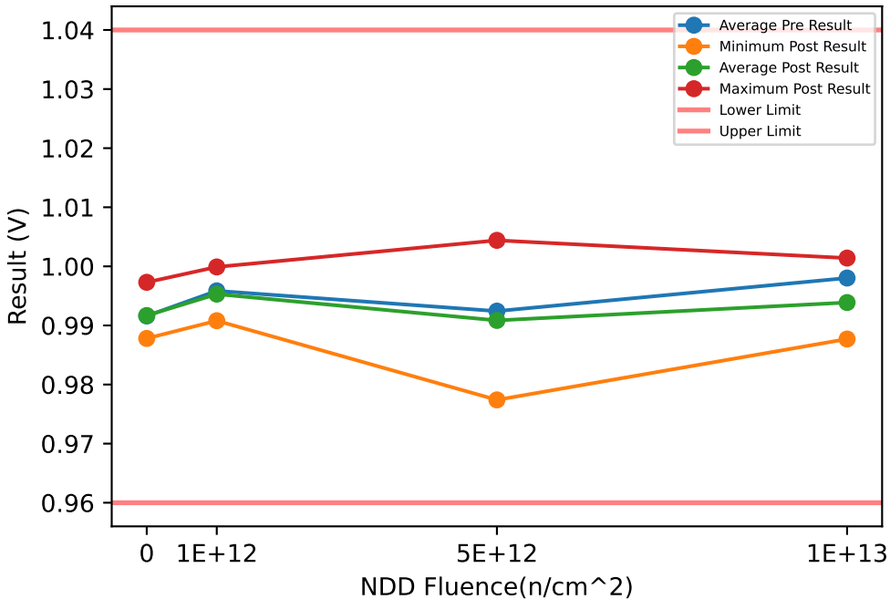
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.0001	1.9999	-0.0002
466	1e+12	NDD	2.0001	2	-0.0001
762	0	CORRELATION	2	2	0
769	1e+12	NDD	2.0003	1.9999	-0.0004
887	1e+12	NDD	1.9999	2	0.0001
891	0	CORRELATION	1.9999	2.0001	0.0002
927	1e+12	NDD	2	2.0001	0.0001
967	5e+12	NDD	2.0001	2	-0.0001
1204	1e+13	NDD	1.9993	2.0001	0.0008
1284	1e+13	NDD	2.0003	2.0001	-0.0002
1292	5e+12	NDD	2.0004	1.9998	-0.0006
1364	1e+13	NDD	1.9999	1.9999	0
1383	5e+12	NDD	2.0001	1.9999	-0.0002
1388	5e+12	NDD	2.0001	2	-0.0001
1427	1e+13	NDD	1.9998	1.9999	0.0001
1666	0	CORRELATION	2.0001	2.0001	0

Test Statistics ()

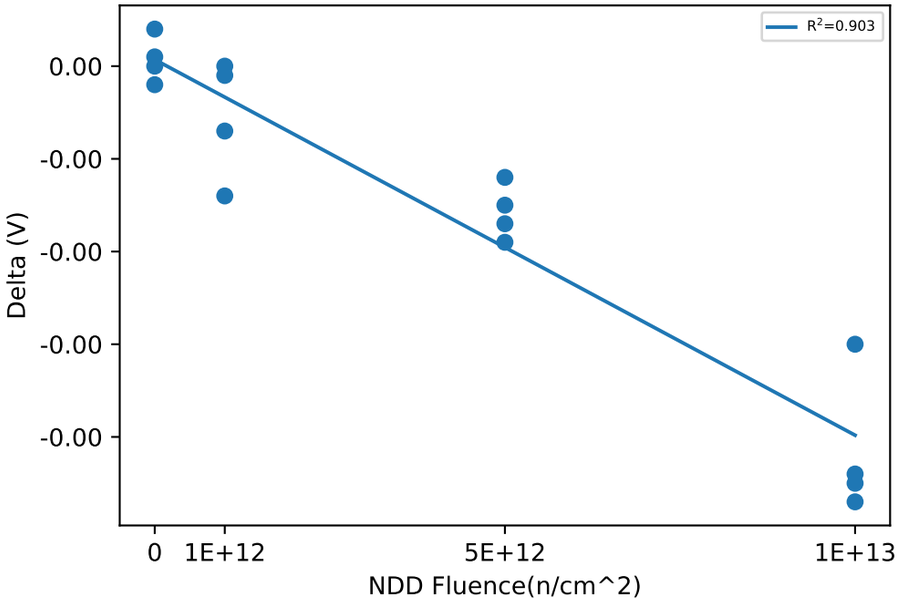
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	1.9999	2	2.0001	9.5743e-05	1.9999	2	2.0001	9.5743e-05	-0.0002	0	0.0002	0.0001633
1e+12	1.9999	2.0001	2.0003	0.00017078	1.9999	2	2.0001	8.165e-05	-0.0004	-7.5e-05	0.0001	0.00023629
5e+12	2.0001	2.0002	2.0004	0.00015	1.9998	1.9999	2	9.5743e-05	-0.0006	-0.00025	-0.0001	0.00023805
1e+13	1.9993	1.9998	2.0003	0.0004113	1.9999	2	2.0001	0.00011547	-0.0002	0.000175	0.0008	0.00043493

Device Test: 28.20 VOLTAGE|OC/CS/14/14/0/0/5/1MHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



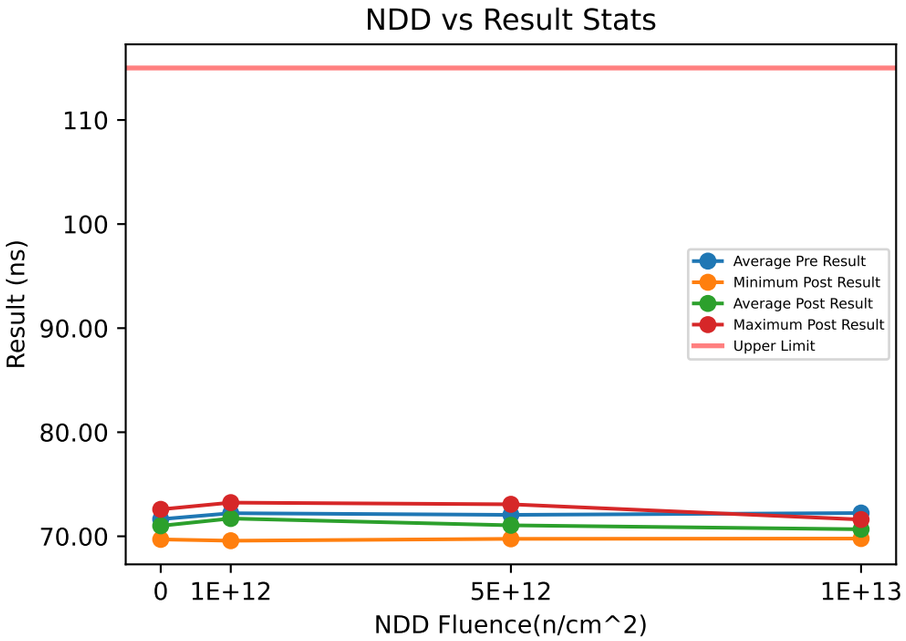
Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

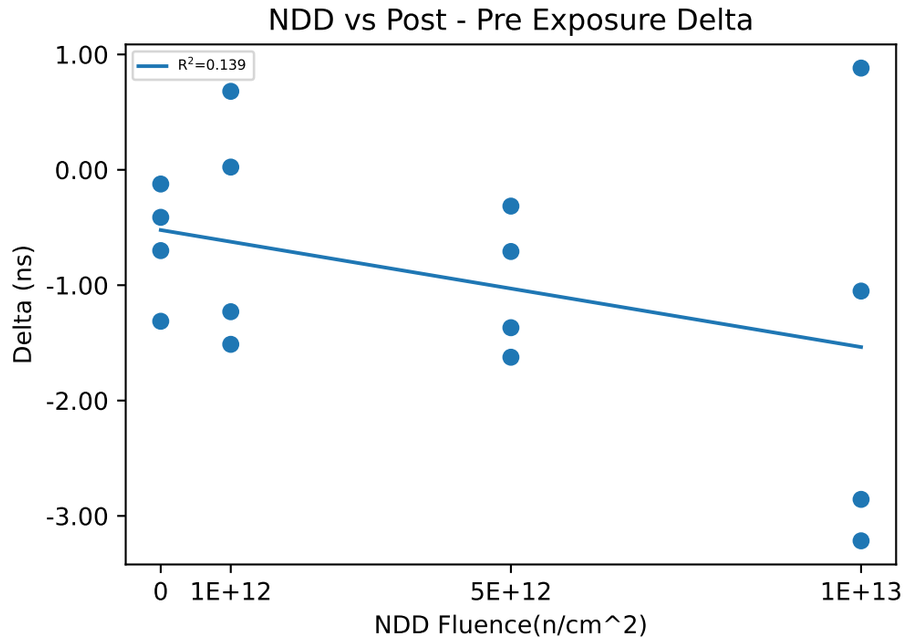
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.988	0.9878	-0.0002
466	1e+12	NDD	0.9969	0.9969	0
762	0	CORRELATION	0.9969	0.9973	0.0004
769	1e+12	NDD	0.9943	0.9936	-0.0007
887	1e+12	NDD	0.9922	0.9908	-0.0014
891	0	CORRELATION	0.9879	0.9879	0
927	1e+12	NDD	1	0.9999	-0.0001
967	5e+12	NDD	1.0056	1.0044	-0.0012
1204	1e+13	NDD	0.9954	0.9909	-0.0045
1284	1e+13	NDD	1.0044	1.0014	-0.003
1292	5e+12	NDD	0.9941	0.9922	-0.0019
1364	1e+13	NDD	0.9999	0.9955	-0.0044
1383	5e+12	NDD	0.9791	0.9774	-0.0017
1388	5e+12	NDD	0.9909	0.9894	-0.0015
1427	1e+13	NDD	0.9924	0.9877	-0.0047
1666	0	CORRELATION	0.9936	0.9937	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9879	0.9916	0.9969	0.0044249	0.9878	0.99167	0.9973	0.004655	-0.0002	7.5e-05	0.0004	0.00025
1e+12	0.9922	0.99585	1	0.003369	0.9908	0.9953	0.9999	0.0039522	-0.0014	-0.00055	0	0.0006455
5e+12	0.9791	0.99243	1.0056	0.010898	0.9774	0.99085	1.0044	0.011082	-0.0019	-0.001575	-0.0012	0.00029861
1e+13	0.9924	0.99802	1.0044	0.00525	0.9877	0.99388	1.0014	0.0059511	-0.0047	-0.00415	-0.003	0.00077675

Device Test: 28.21 TIMING|DELAY/CS/4.5/4.5/0/0/4.5/100kHz//@CS_ILIM_DELAY





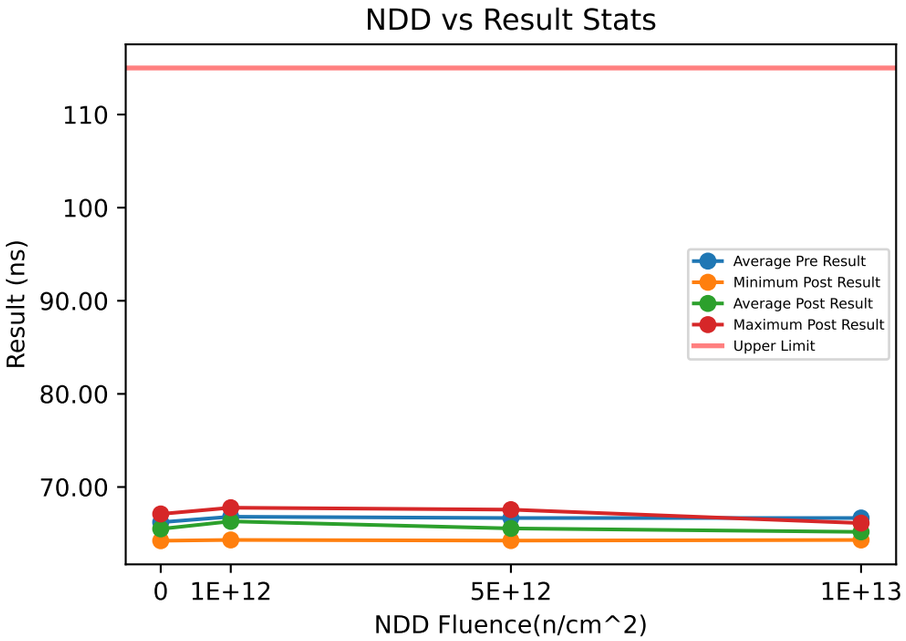
Test Results (Upper Limit = 115.0 (ns))

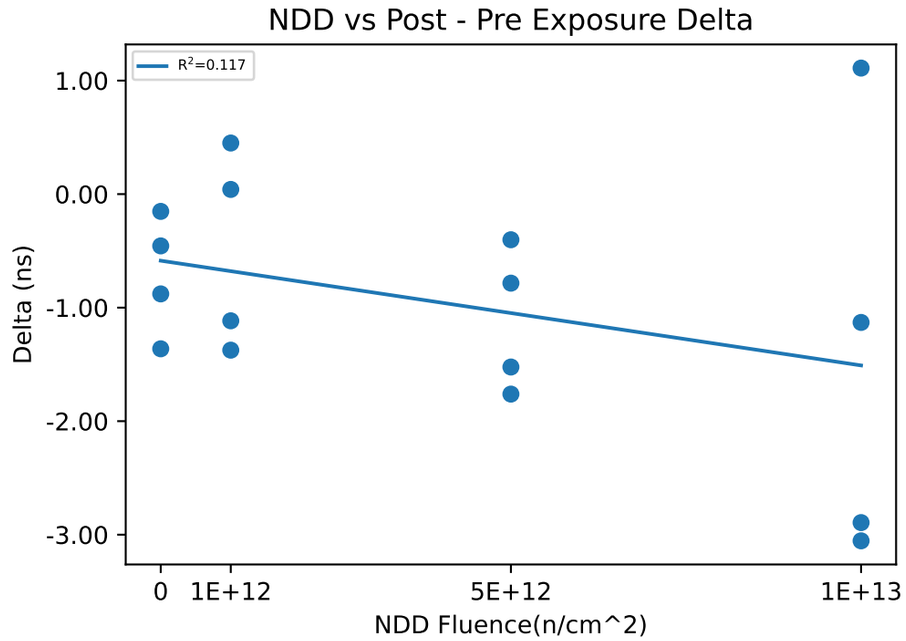
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	71.972	70.659	-1.3127
466	1e+12	NDD	72.83	72.853	0.0237
762	0	CORRELATION	71.205	71.082	-0.1231
769	1e+12	NDD	74.465	73.235	-1.2299
887	1e+12	NDD	71.087	69.575	-1.5127
891	0	CORRELATION	70.114	69.702	-0.4118
927	1e+12	NDD	70.489	71.169	0.6804
967	5e+12	NDD	74.442	73.074	-1.3685
1204	1e+13	NDD	70.833	69.782	-1.051
1284	1e+13	NDD	72.859	70.002	-2.8566
1292	5e+12	NDD	70.463	69.755	-0.708
1364	1e+13	NDD	74.519	71.303	-3.2158
1383	5e+12	NDD	71.154	70.84	-0.3146
1388	5e+12	NDD	72.177	70.553	-1.6244
1427	1e+13	NDD	70.73	71.611	0.8819
1666	0	CORRELATION	73.289	72.589	-0.7003

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	70.114	71.645	73.289	1.3352	69.702	71.008	72.589	1.2017	-1.3127	-0.63697	-0.1231	0.50839
1e+12	70.489	72.218	74.465	1.7973	69.575	71.708	73.235	1.6818	-1.5127	-0.50962	0.6804	1.0369
5e+12	70.463	72.059	74.442	1.7379	69.755	71.055	73.074	1.4218	-1.6244	-1.0039	-0.3146	0.60018
1e+13	70.73	72.235	74.519	1.8106	69.782	70.675	71.611	0.91651	-3.2158	-1.5604	0.8819	1.8837

Device Test: 28.22 TIMING|DELAY/CS/5/5/0/0/5/100kHz//@CS_ILIM_DELAY





Test Results (Upper Limit = 115.0 (ns))

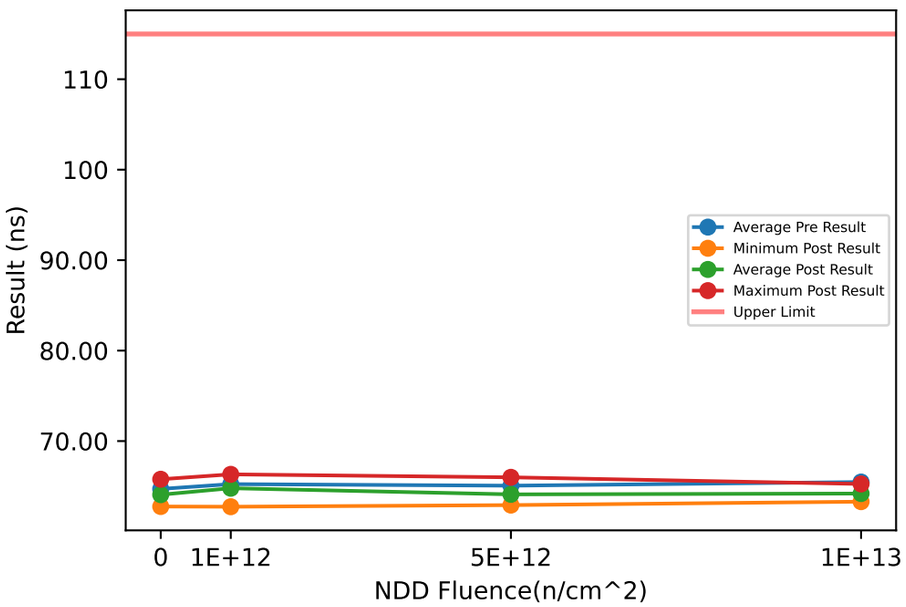
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	66.518	65.156	-1.3625
466	1e+12	NDD	67.457	67.499	0.0413
762	0	CORRELATION	65.67	65.518	-0.1521
769	1e+12	NDD	68.894	67.778	-1.1159
887	1e+12	NDD	65.69	64.316	-1.3745
891	0	CORRELATION	64.689	64.232	-0.4561
927	1e+12	NDD	65.202	65.652	0.4501
967	5e+12	NDD	69.093	67.57	-1.523
1204	1e+13	NDD	65.442	64.311	-1.1303
1284	1e+13	NDD	67.428	64.534	-2.8935
1292	5e+12	NDD	65.032	64.247	-0.7843
1364	1e+13	NDD	68.807	65.753	-3.054
1383	5e+12	NDD	65.769	65.367	-0.4019
1388	5e+12	NDD	66.79	65.028	-1.7616
1427	1e+13	NDD	65.013	66.123	1.1103
1666	0	CORRELATION	67.985	67.106	-0.8789

Test Statistics (ns)

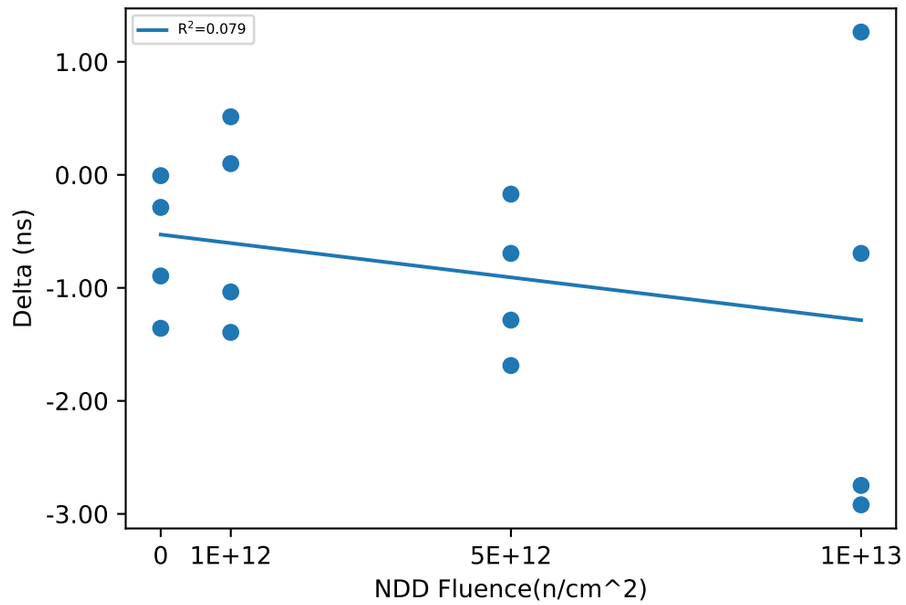
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.689	66.215	67.985	1.3967	64.232	65.503	67.106	1.198	-1.3625	-0.7124	-0.1521	0.52598
1e+12	65.202	66.811	68.894	1.6933	64.316	66.311	67.778	1.6308	-1.3745	-0.49975	0.4501	0.88313
5e+12	65.032	66.671	69.093	1.7685	64.247	65.553	67.57	1.424	-1.7616	-1.1177	-0.4019	0.63309
1e+13	65.013	66.672	68.807	1.7696	64.311	65.18	66.123	0.89228	-3.054	-1.4919	1.1103	1.9414

Device Test: 28.23 TIMING|DELAY/CS/12/12/0/0/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 115.0 (ns))

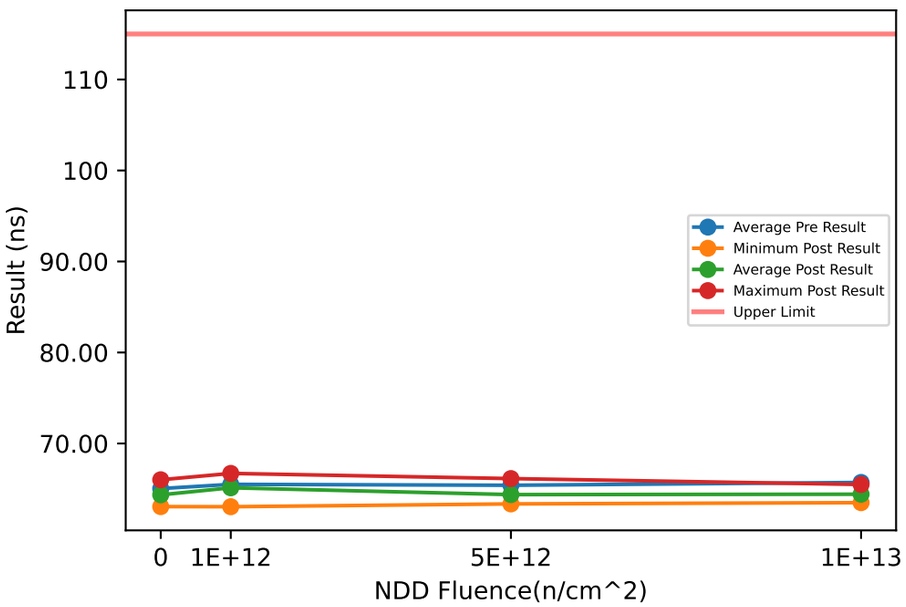
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	65.135	63.778	-1.3578
466	1e+12	NDD	65.814	65.913	0.0992
762	0	CORRELATION	63.98	63.972	-0.0071
769	1e+12	NDD	67.359	66.323	-1.0362
887	1e+12	NDD	64.138	62.745	-1.3938
891	0	CORRELATION	63.055	62.767	-0.2882
927	1e+12	NDD	63.659	64.172	0.5133
967	5e+12	NDD	67.279	65.994	-1.2854
1204	1e+13	NDD	63.998	63.303	-0.6953
1284	1e+13	NDD	66.514	63.766	-2.748
1292	5e+12	NDD	63.619	62.924	-0.6951
1364	1e+13	NDD	67.386	64.466	-2.9196
1383	5e+12	NDD	64.122	63.951	-0.1708
1388	5e+12	NDD	65.261	63.573	-1.6874
1427	1e+13	NDD	63.998	65.261	1.2631
1666	0	CORRELATION	66.676	65.781	-0.8947

Test Statistics (ns)

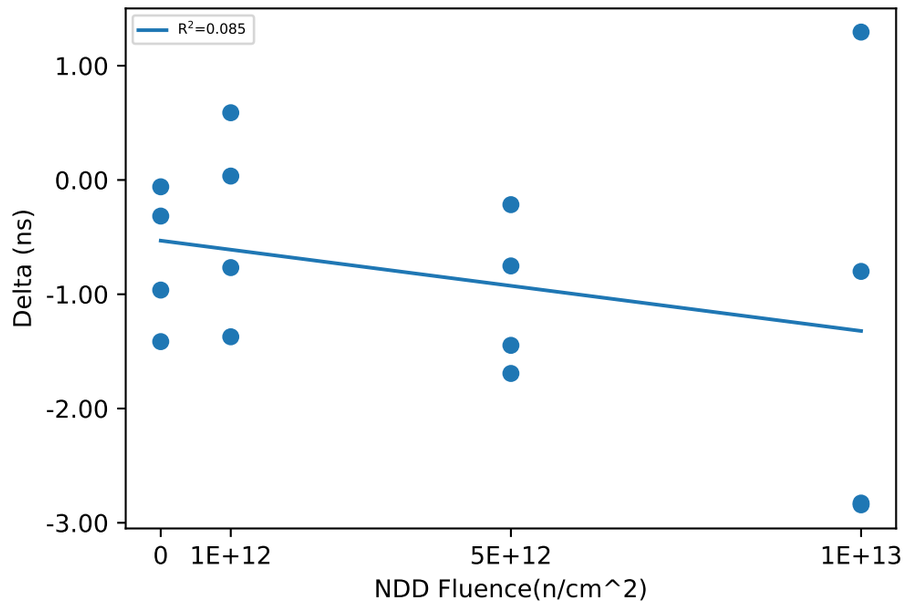
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.055	64.712	66.676	1.5617	62.767	64.075	65.781	1.2544	-1.3578	-0.63695	-0.0071	0.60674
1e+12	63.659	65.242	67.359	1.6865	62.745	64.788	66.323	1.6509	-1.3938	-0.45438	0.5133	0.90625
5e+12	63.619	65.07	67.279	1.625	62.924	64.111	65.994	1.3253	-1.6874	-0.95968	-0.1708	0.66533
1e+13	63.998	65.474	67.386	1.7412	63.303	64.199	65.261	0.85421	-2.9196	-1.275	1.2631	1.9708

Device Test: 28.24 TIMING|DELAY/CS/14/14/0/0/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



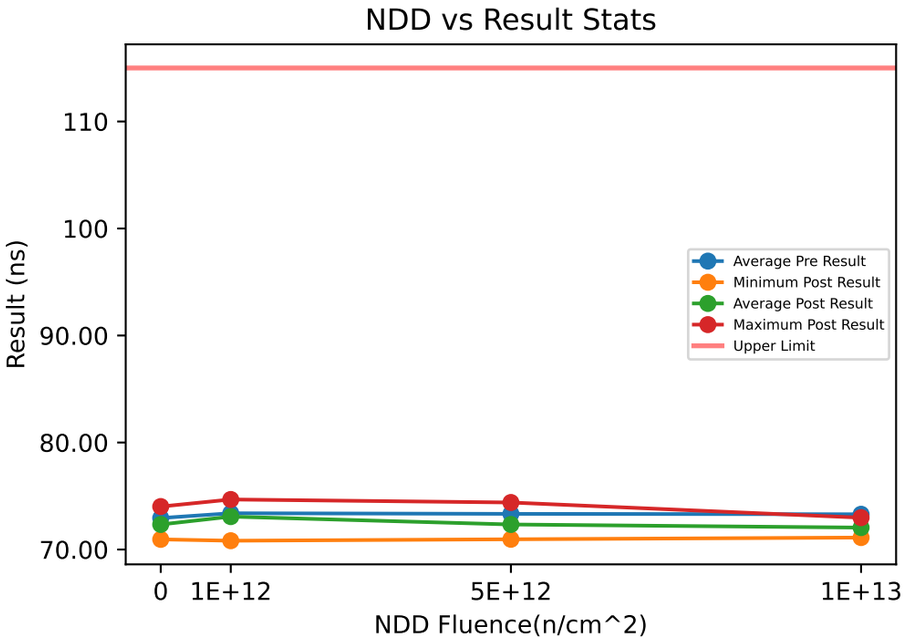
Test Results (Upper Limit = 115.0 (ns))

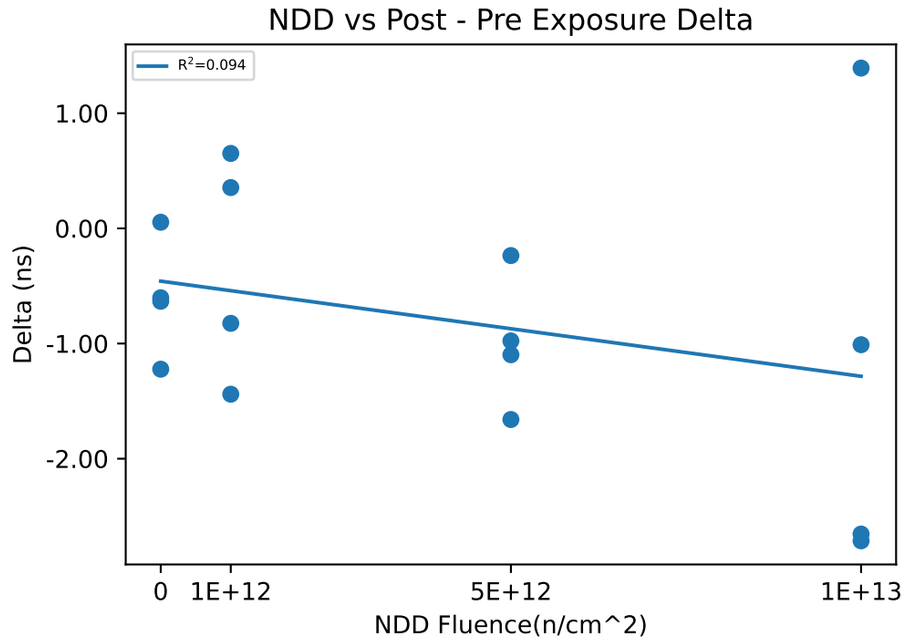
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	65.459	64.045	-1.4145
466	1e+12	NDD	66.295	66.329	0.0343
762	0	CORRELATION	64.37	64.31	-0.0596
769	1e+12	NDD	67.479	66.712	-0.7668
887	1e+12	NDD	64.423	63.051	-1.3722
891	0	CORRELATION	63.378	63.062	-0.3158
927	1e+12	NDD	63.843	64.432	0.5886
967	5e+12	NDD	67.59	66.143	-1.4472
1204	1e+13	NDD	64.297	63.497	-0.8
1284	1e+13	NDD	66.788	63.945	-2.8428
1292	5e+12	NDD	64.113	63.361	-0.7521
1364	1e+13	NDD	67.589	64.761	-2.8275
1383	5e+12	NDD	64.36	64.144	-0.2159
1388	5e+12	NDD	65.575	63.882	-1.6931
1427	1e+13	NDD	64.2	65.494	1.2945
1666	0	CORRELATION	66.976	66.013	-0.9633

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	63.378	65.046	66.976	1.5421	63.062	64.357	66.013	1.2269	-1.4145	-0.6883	-0.0596	0.61563
1e+12	63.843	65.51	67.479	1.6785	63.051	65.131	66.712	1.7079	-1.3722	-0.37903	0.5886	0.86485
5e+12	64.113	65.41	67.59	1.5881	63.361	64.383	66.143	1.2181	-1.6931	-1.0271	-0.2159	0.67174
1e+13	64.2	65.718	67.589	1.7289	63.497	64.424	65.494	0.8847	-2.8428	-1.2939	1.2945	1.9744

Device Test: 28.25 TIMING|DELAY/CS/4.5/4.5/0/1000/4.5/100kHz//@CS_ILIM_DELAY





Test Results (Upper Limit = 115.0 (ns))

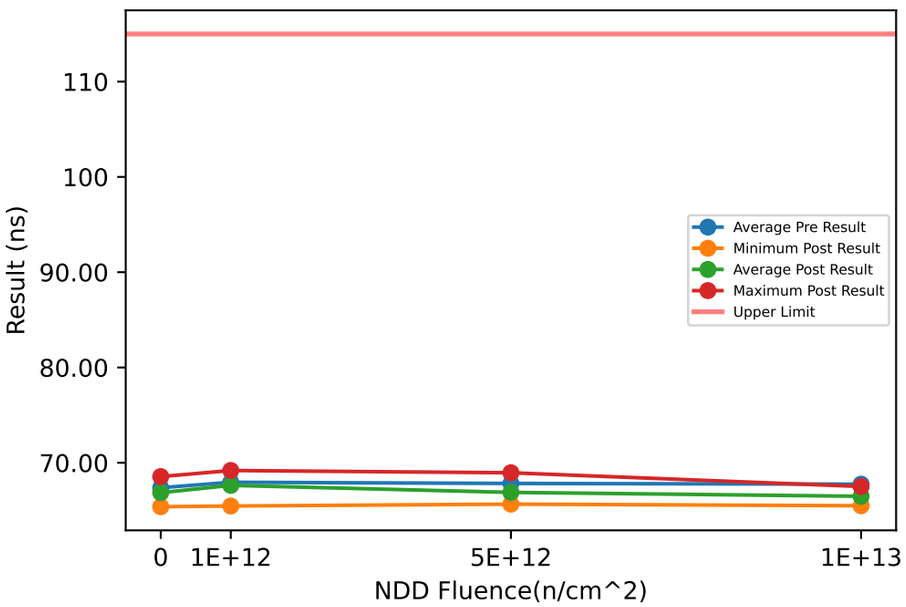
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	73.189	71.966	-1.2228
466	1e+12	NDD	73.98	74.335	0.3544
762	0	CORRELATION	72.382	72.435	0.0534
769	1e+12	NDD	75.501	74.676	-0.8247
887	1e+12	NDD	72.263	70.823	-1.4401
891	0	CORRELATION	71.552	70.949	-0.6024
927	1e+12	NDD	71.819	72.469	0.6508
967	5e+12	NDD	75.492	74.395	-1.0972
1204	1e+13	NDD	72.129	71.118	-1.0102
1284	1e+13	NDD	74.056	71.343	-2.7132
1292	5e+12	NDD	71.935	70.958	-0.9773
1364	1e+13	NDD	75.417	72.762	-2.6546
1383	5e+12	NDD	72.332	72.096	-0.2361
1388	5e+12	NDD	73.577	71.917	-1.6598
1427	1e+13	NDD	71.585	72.977	1.3921
1666	0	CORRELATION	74.649	74.016	-0.6329

Test Statistics (ns)

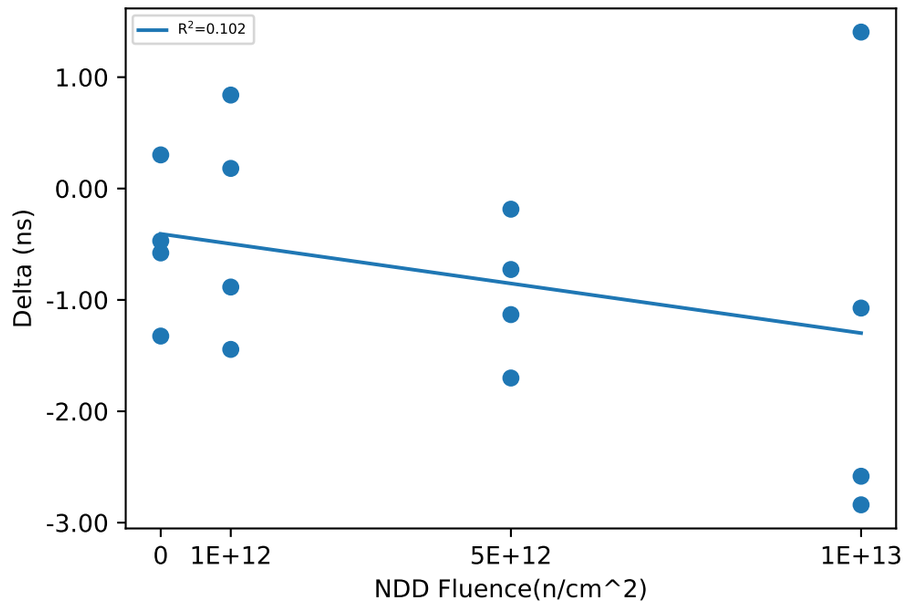
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	71.552	72.943	74.649	1.3193	70.949	72.342	74.016	1.277	-1.2228	-0.60118	0.0534	0.5215
1e+12	71.819	73.391	75.501	1.6876	70.823	73.076	74.676	1.7877	-1.4401	-0.3149	0.6508	0.9843
5e+12	71.935	73.334	75.492	1.5999	70.958	72.341	74.395	1.4575	-1.6598	-0.9926	-0.2361	0.58555
1e+13	71.585	73.297	75.417	1.7669	71.118	72.05	72.977	0.95478	-2.7132	-1.2465	1.3921	1.928

Device Test: 28.26 TIMING|DELAY/CS/5/5/0/1000/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Upper Limit = 115.0 (ns))

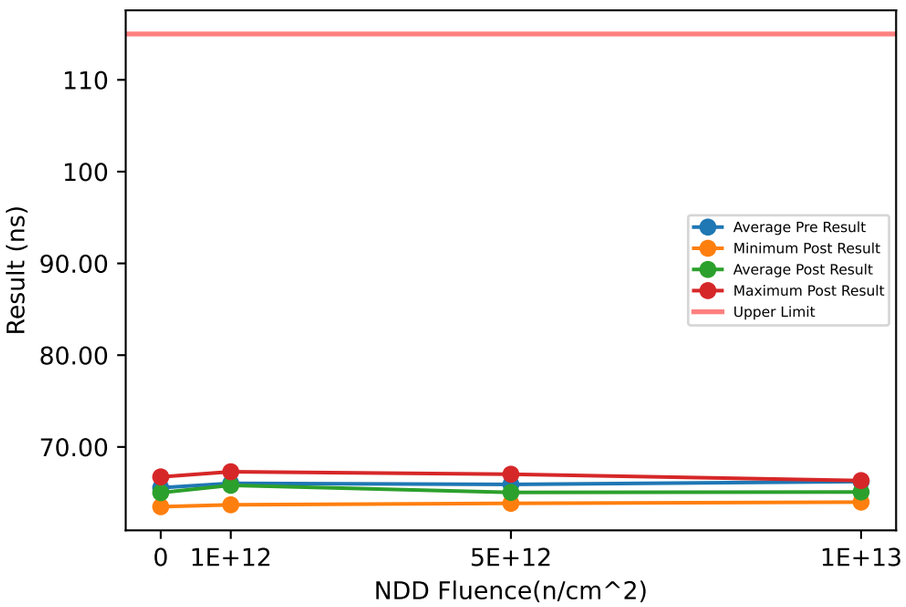
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	67.765	66.44	-1.3247
466	1e+12	NDD	68.622	68.803	0.1807
762	0	CORRELATION	66.765	67.067	0.302
769	1e+12	NDD	70.074	69.189	-0.8845
887	1e+12	NDD	66.907	65.463	-1.4444
891	0	CORRELATION	65.859	65.389	-0.4703
927	1e+12	NDD	66.222	67.061	0.8393
967	5e+12	NDD	70.084	68.952	-1.132
1204	1e+13	NDD	66.567	65.493	-1.0733
1284	1e+13	NDD	68.578	65.738	-2.8399
1292	5e+12	NDD	66.386	65.659	-0.7271
1364	1e+13	NDD	69.767	67.184	-2.5833
1383	5e+12	NDD	66.829	66.644	-0.1856
1388	5e+12	NDD	68.022	66.321	-1.7013
1427	1e+13	NDD	66.106	67.511	1.4048
1666	0	CORRELATION	69.128	68.55	-0.5783

Test Statistics (ns)

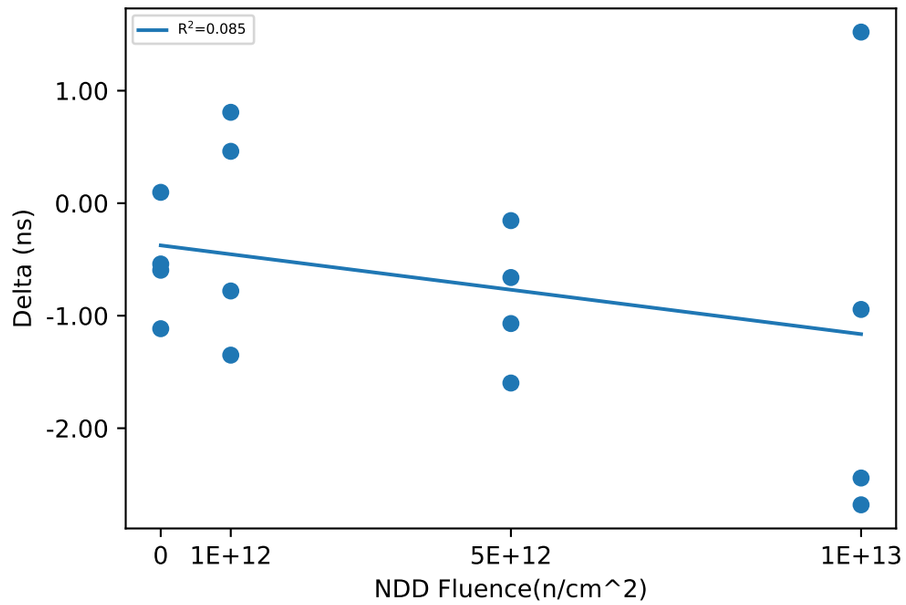
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	65.859	67.379	69.128	1.402	65.389	66.862	68.55	1.3217	-1.3247	-0.51782	0.302	0.6656
1e+12	66.222	67.956	70.074	1.7355	65.463	67.629	69.189	1.7154	-1.4444	-0.32722	0.8393	1.0291
5e+12	66.386	67.83	70.084	1.6537	65.659	66.894	68.952	1.4321	-1.7013	-0.9365	-0.1856	0.64053
1e+13	66.106	67.754	69.767	1.7183	65.493	66.482	67.511	1.0134	-2.8399	-1.2729	1.4048	1.9479

Device Test: 28.27 TIMING|DELAY/CS/12/12/0/1000/5/100kHz//@CS_ILIM_DELAY

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



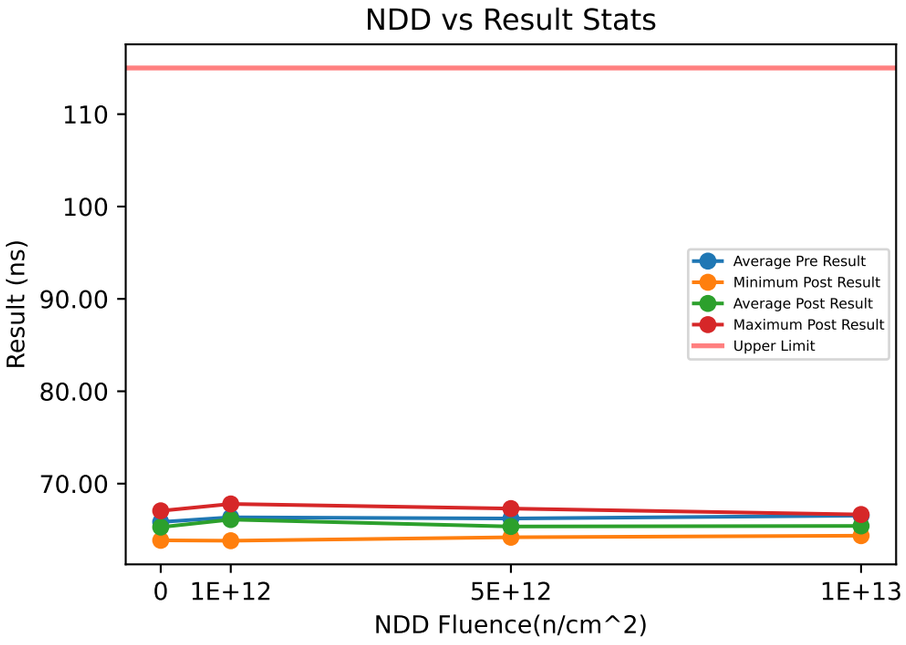
Test Results (Upper Limit = 115.0 (ns))

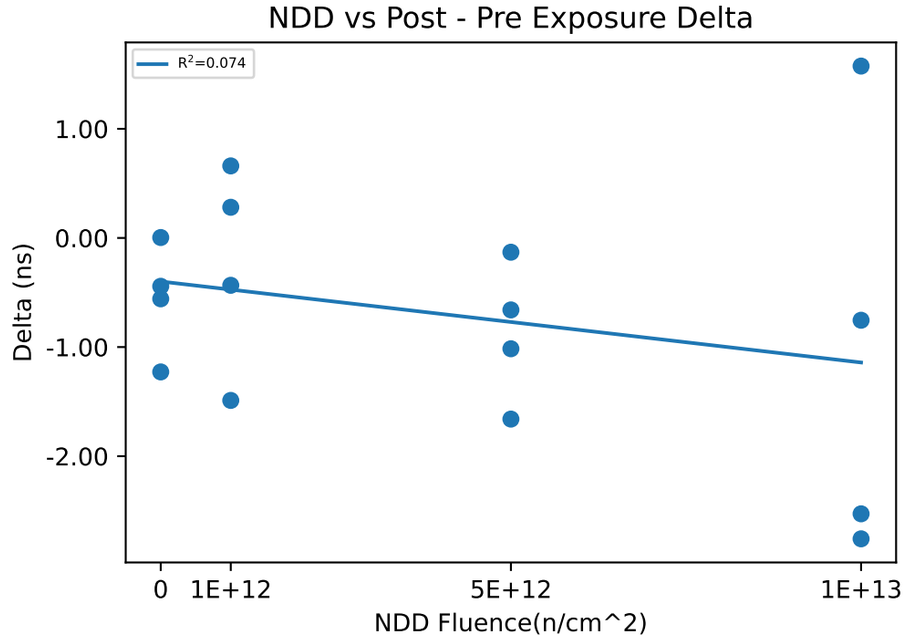
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	65.942	64.826	-1.1155
466	1e+12	NDD	66.705	67.166	0.4611
762	0	CORRELATION	64.914	65.01	0.0965
769	1e+12	NDD	68.077	67.297	-0.7802
887	1e+12	NDD	65.045	63.695	-1.3505
891	0	CORRELATION	64.081	63.485	-0.5958
927	1e+12	NDD	64.306	65.113	0.8078
967	5e+12	NDD	68.095	67.025	-1.0698
1204	1e+13	NDD	64.932	63.987	-0.9444
1284	1e+13	NDD	67.232	64.551	-2.6809
1292	5e+12	NDD	64.514	63.853	-0.6607
1364	1e+13	NDD	67.93	65.487	-2.4426
1383	5e+12	NDD	64.876	64.721	-0.1549
1388	5e+12	NDD	66.176	64.578	-1.5984
1427	1e+13	NDD	64.812	66.333	1.5209
1666	0	CORRELATION	67.276	66.736	-0.5403

Test Statistics (ns)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.081	65.553	67.276	1.3777	63.485	65.014	66.736	1.3337	-1.1155	-0.53878	0.0965	0.49647
1e+12	64.306	66.033	68.077	1.692	63.695	65.818	67.297	1.7328	-1.3505	-0.21545	0.8078	1.0185
5e+12	64.514	65.915	68.095	1.619	63.853	65.044	67.025	1.3741	-1.5984	-0.87095	-0.1549	0.61255
1e+13	64.812	66.226	67.93	1.5906	63.987	65.09	66.333	1.0342	-2.6809	-1.1367	1.5209	1.9313

Device Test: 28.28 TIMING|DELAY/CS/14/14/0/1000/5/100kHz//@CS_ILIM_DELAY





Test Results (Upper Limit = 115.0 (ns))

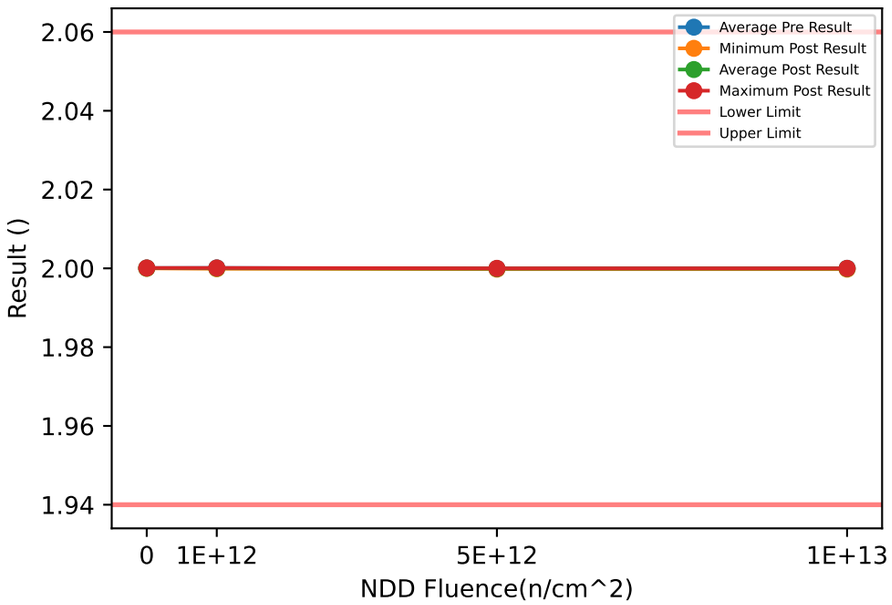
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	66.286	65.058	-1.2278
466	1e+12	NDD	67.115	67.396	0.2811
762	0	CORRELATION	65.189	65.193	0.0039
769	1e+12	NDD	68.235	67.801	-0.434
887	1e+12	NDD	65.309	63.82	-1.489
891	0	CORRELATION	64.306	63.863	-0.443
927	1e+12	NDD	64.758	65.418	0.6603
967	5e+12	NDD	68.316	67.3	-1.0155
1204	1e+13	NDD	65.121	64.366	-0.7542
1284	1e+13	NDD	67.615	64.858	-2.7573
1292	5e+12	NDD	64.854	64.195	-0.6595
1364	1e+13	NDD	68.33	65.802	-2.5282
1383	5e+12	NDD	65.232	65.102	-0.1307
1388	5e+12	NDD	66.501	64.841	-1.66
1427	1e+13	NDD	65.082	66.657	1.5751
1666	0	CORRELATION	67.614	67.056	-0.5579

Test Statistics (ns)

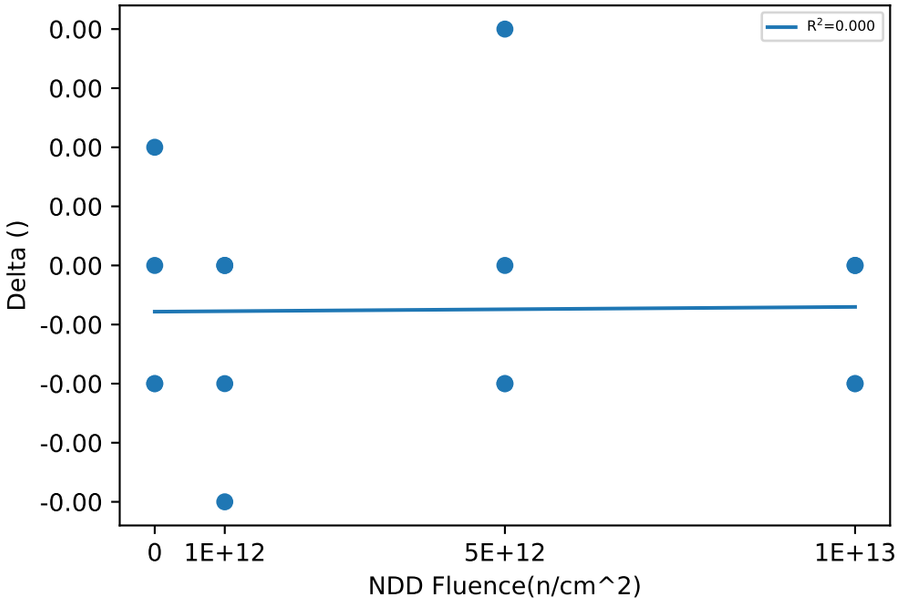
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	64.306	65.849	67.614	1.4286	63.863	65.293	67.056	1.319	-1.2278	-0.5562	0.0039	0.50911
1e+12	64.758	66.354	68.235	1.6078	63.82	66.109	67.801	1.8469	-1.489	-0.2454	0.6603	0.94509
5e+12	64.854	66.226	68.316	1.5613	64.195	65.359	67.3	1.349	-1.66	-0.86642	-0.1307	0.6419
1e+13	65.082	66.537	68.33	1.6834	64.366	65.421	66.657	1.0171	-2.7573	-1.1162	1.5751	2.0051

Device Test: 28.3 LEVEL|RATIO/CS/12/12/0/0/5/500kHz//@C_CS_R

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

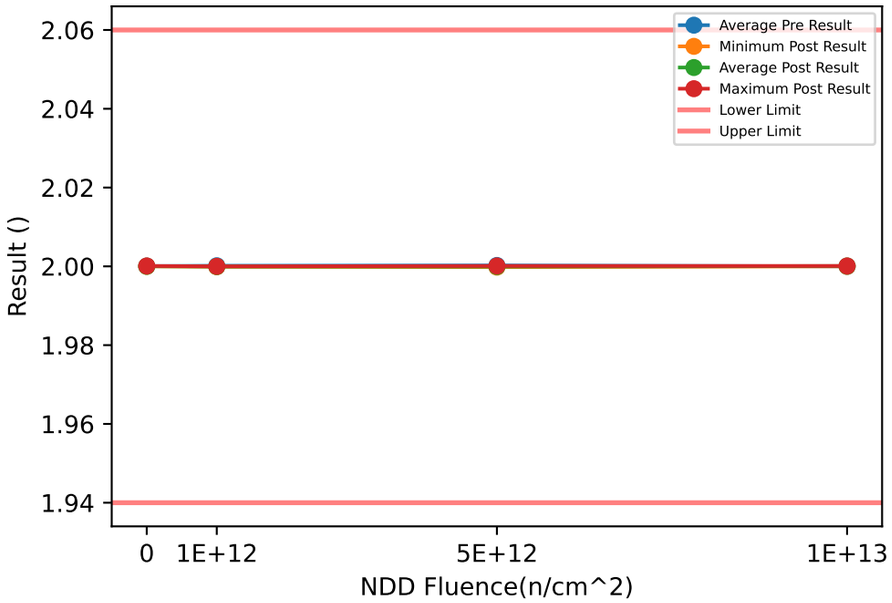
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.0002	2.0001	-0.0001
466	1e+12	NDD	2.0001	1.9999	-0.0002
762	0	CORRELATION	2	2	0
769	1e+12	NDD	2.0001	2	-0.0001
887	1e+12	NDD	2.0001	2.0001	0
891	0	CORRELATION	2.0001	2	-0.0001
927	1e+12	NDD	2.0001	2.0001	0
967	5e+12	NDD	1.9999	1.9999	0
1204	1e+13	NDD	1.9999	1.9998	-0.0001
1284	1e+13	NDD	2	2	0
1292	5e+12	NDD	1.9999	1.9998	-0.0001
1364	1e+13	NDD	2	2	0
1383	5e+12	NDD	2.0001	2	-0.0001
1388	5e+12	NDD	1.9998	2	0.0002
1427	1e+13	NDD	2.0001	2	-0.0001
1666	0	CORRELATION	2	2.0001	0.0001

Test Statistics ()

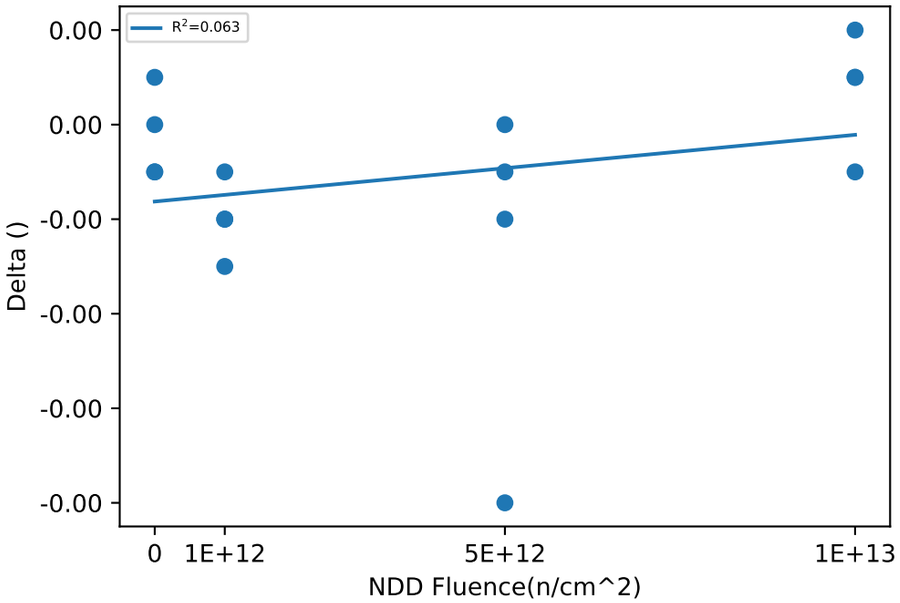
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2	2.0001	2.0002	9.5743e-05	2	2	2.0001	5.7735e-05	-0.0001	-2.5e-05	0.0001	9.5743e-05
1e+12	2.0001	2.0001	2.0001	0	1.9999	2	2.0001	9.5743e-05	-0.0002	-7.5e-05	0	9.5743e-05
5e+12	1.9998	1.9999	2.0001	0.00012583	1.9998	1.9999	2	9.5743e-05	-0.0001	-5.5511e-17	0.0002	0.00014142
1e+13	1.9999	2	2.0001	8.165e-05	1.9998	2	2	0.0001	-0.0001	-5e-05	0	5.7735e-05

Device Test: 28.4 LEVEL|RATIO/CS/14/14/0/0/5/500kHz//@C_CS_R

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 1.94, Upper Limit = 2.06 ())

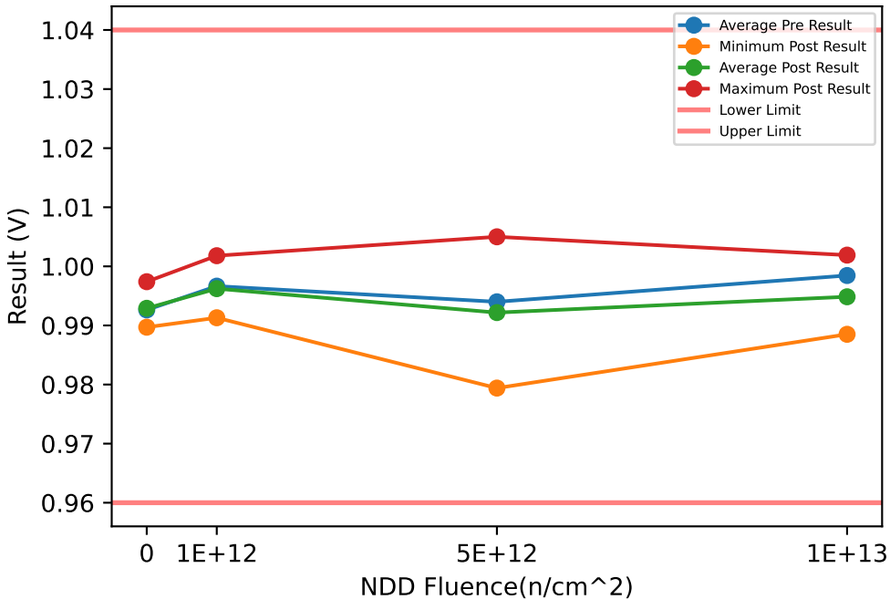
Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	2.0001	2	-0.0001
466	1e+12	NDD	2.0001	2	-0.0001
762	0	CORRELATION	2	2.0001	0.0001
769	1e+12	NDD	2.0001	1.9999	-0.0002
887	1e+12	NDD	2.0001	1.9999	-0.0002
891	0	CORRELATION	2	2	0
927	1e+12	NDD	2.0003	2	-0.0003
967	5e+12	NDD	2.0001	1.9999	-0.0002
1204	1e+13	NDD	2.0001	2	-0.0001
1284	1e+13	NDD	2	2.0001	0.0001
1292	5e+12	NDD	2.0006	1.9998	-0.0008
1364	1e+13	NDD	1.9999	2.0001	0.0002
1383	5e+12	NDD	2.0001	2.0001	0
1388	5e+12	NDD	2.0001	2	-0.0001
1427	1e+13	NDD	2	2.0001	0.0001
1666	0	CORRELATION	2.0001	2	-0.0001

Test Statistics ()

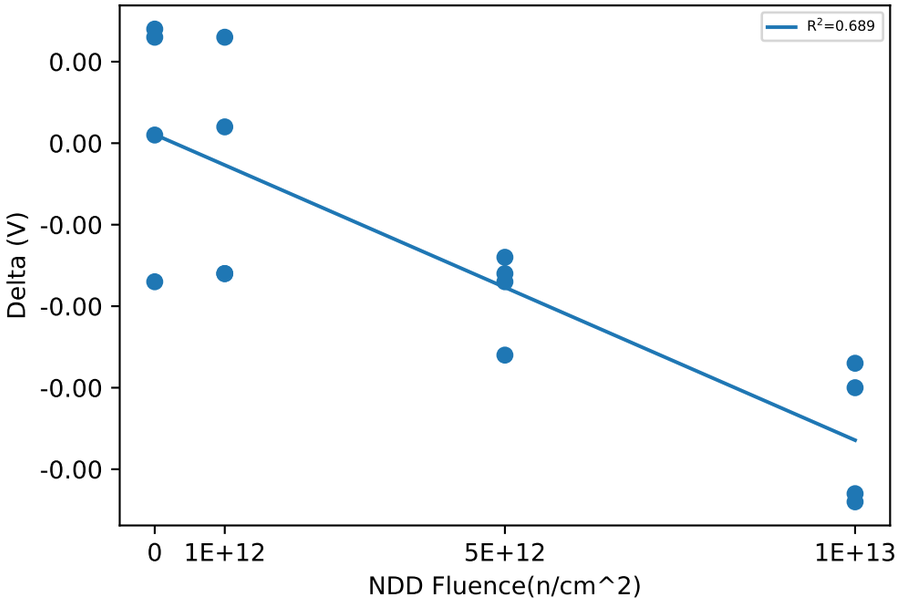
Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	2	2	2.0001	5.7735e-05	2	2	2.0001	5e-05	-0.0001	-2.5e-05	0.0001	9.5743e-05
1e+12	2.0001	2.0002	2.0003	0.0001	1.9999	2	2	5.7735e-05	-0.0003	-0.0002	-0.0001	8.165e-05
5e+12	2.0001	2.0002	2.0006	0.00025	1.9998	2	2.0001	0.0001291	-0.0008	-0.000275	0	0.0003594
1e+13	1.9999	2	2.0001	8.165e-05	2	2.0001	2.0001	5e-05	-0.0001	7.5e-05	0.0002	0.00012583

Device Test: 28.9 VOLTAGE|OC/CS/4.5/4.5/0/0/4.5/100kHz//@V_CS_ILIM_OC

NDD vs Result Stats



NDD vs Post - Pre Exposure Delta



Test Results (Lower Limit = 0.96, Upper Limit = 1.04 (V))

Serial #	Fluence(n/cm^2)	Exposure Conditions	Pre Result	Post Result	Delta
406	0	CORRELATION	0.9885	0.9899	0.0014
466	1e+12	NDD	0.9974	0.9976	0.0002
762	0	CORRELATION	0.9991	0.9974	-0.0017
769	1e+12	NDD	0.9958	0.9942	-0.0016
887	1e+12	NDD	0.9929	0.9913	-0.0016
891	0	CORRELATION	0.9884	0.9897	0.0013
927	1e+12	NDD	1.0005	1.0018	0.0013
967	5e+12	NDD	1.0076	1.005	-0.0026
1204	1e+13	NDD	0.9959	0.9916	-0.0043
1284	1e+13	NDD	1.0049	1.0019	-0.003
1292	5e+12	NDD	0.9945	0.9928	-0.0017
1364	1e+13	NDD	1.0001	0.9974	-0.0027
1383	5e+12	NDD	0.981	0.9794	-0.0016
1388	5e+12	NDD	0.9929	0.9915	-0.0014
1427	1e+13	NDD	0.9929	0.9885	-0.0044
1666	0	CORRELATION	0.9945	0.9946	0.0001

Test Statistics (V)

Fluence(n/cm^2)	Pre Exposure Min	Pre Exposure Avg	Pre Exposure Max	Pre Exposure Std	Post Exposure Min	Post Exposure Avg	Post Exposure Max	Post Exposure Std	Min Delta	Avg Delta	Max Delta	Std Delta
0	0.9884	0.99262	0.9991	0.0051739	0.9897	0.9929	0.9974	0.0037585	-0.0017	0.000275	0.0014	0.0014431
1e+12	0.9929	0.99665	1.0005	0.0031712	0.9913	0.99623	1.0018	0.0045213	-0.0016	-0.000425	0.0013	0.0014292
5e+12	0.981	0.994	1.0076	0.010885	0.9794	0.99218	1.005	0.010465	-0.0026	-0.001825	-0.0014	0.00053151
1e+13	0.9929	0.99845	1.0049	0.0052163	0.9885	0.99485	1.0019	0.0059747	-0.0044	-0.0036	-0.0027	0.0008756

IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES “AS IS” AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you fully indemnify TI and its representatives against any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI’s products are provided subject to TI’s Terms of Sale, TI’s General Quality Guidelines, or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI’s provision of these resources does not expand or otherwise alter TI’s applicable warranties or warranty disclaimers for TI products. Unless TI explicitly designates a product as custom or customer-specified, TI products are standard, catalog, general purpose devices.

TI objects to and rejects any additional or different terms you may propose.

Copyright © 2026, Texas Instruments Incorporated

Last updated 10/2025